Radiation Report

TPS7H6005-SP Total Ionizing Dose (TID) Preliminary Report

ABSTRACT

This report discusses the results of the total ionizing dose (TID) testing for the Texas Instruments TPS7H6005-SP radiation hardness-assured 1.3A, 2.5A, half bridge gate driver. The study was done to determine TID effects at 100krad (Si) High Dose Rate (HDR). The results show that all samples pass within device specified test limits.

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Trademarks

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1 Device Information

1.1 Product Description

The TPS7H6005-SP is a 200V radiation-hardness-assured, high voltage gate driver for space applications. The TPS7H6005-SP is designed for high frequency, high efficiency applications. The driver features adjustable dead time capability, small 30ns propagation delay and 5.5ns high-side and low-side matching. This part also includes internal high-side and low-side LDOs which specifies a drive voltage of 5V regardless of supply voltage. The TPS7H6005-SP is packaged in a plastic 56-pin HTSSOP DCA package.

1.2 Device Details

Testing was performed per MIL-STD-883, Test Method 1019, with a sample size per MIL-PRF-38535, Appendix C, test condition A (high dose rate).

Table 1-1. Device and Exposure Details

RHA TID Details: Up to 100 krad(Si)	
TI Part Number	TPS7H6005-SP
Device Function	Half Bridge Gate Driver
Die Name	RTPS7H6005A0VM
Package	56-pin HTSSOP DCA
Technology	LBC7 (250nm Linear BiCMOS)
Quantity tested	HDR : • Three biased and three unbiased units at 50krad(Si) levels • Three biased and three unbiased units at 100krad(Si) levels • One correlation unit
Lot Accept/Reject	Passes 100krad(Si); no observed fails
HDR Radiation Facility	Texas Instruments CLAB Dallas, Texas
Die Lot Number and Assembly Lot Number	3042615TI1 / 4344965ML4
HDR Dose Rate	181.0 rad (Si) / s
HDR Radiation Source	Gammacell 220 Excel (GC-220E) Co-60
Irradiation and Test Temperature	Ambient, room temperature controlled to 25°C ±6°C per MIL-STD-883 and MIL-STD-750

Figure 1-1. Device Used in Exposure (Front)

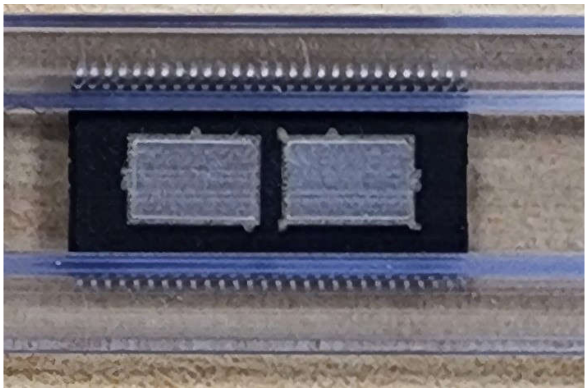


Figure 1-2. Device Used in Exposure (Back)

2 Total Dose Test Setup

2.1 Test Overview

The TPS7H6005-SP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, condition A was used. For this test, the product was irradiated up to the target radiation level, and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). All devices remained functional passing all parametric test limits.

2.2 Test Description and Facilities

The TPS7H6005-SP HDR exposure was performed on biased devices in a Co-60 Gammacell at the TI Dallas C-Lab facility in Dallas, Texas. The unattenuated dose rate of this cell is 181 rad (Si) / s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and post-radiation electrical testing at TI's Dallas Forest Lane facility. Test limit guard bands are set within SMD electrical test limits.

Post-radiation measurements were taken within 30 minutes after removing device from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

The devices under HDR exposure were tested in two conditions, biased and unbiased, as described in the following sections.

2.3.1 Unbiased

For the unbiased HDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Shows the HDR bias diagram and schematic

Table 2-1. DUT Power Supply Bias and Vout Measurements

Power Supply Bias				
	Edge Connector	BUS	Typical	Comments
Power Supply	BUS A	VIN	14VDC	14VDC - Fixed power supply
	BUS D	BOOT	14VDC	14VDCWRTSW - Floating power supply WRT to SW
	BUS B	ASW	150V	Increase HV gradually. Recommend using safety interlock HV protection when working with high voltage.
DUT Vout Measurements				
VOUT Test Points	TP_PGOOD	ON	5V	LS is ON
	TP_LO	PWM_LI	1.8V	PWM mode
	TP_HO	PWM_LI DC WRT ASW	3.51V	PWM mode
	TP_SW	SW = PSW = ASW	150V	SW = PSW = ASW
	PWM_LI	DUT Mon	1.85V	DUT monitor edge connector

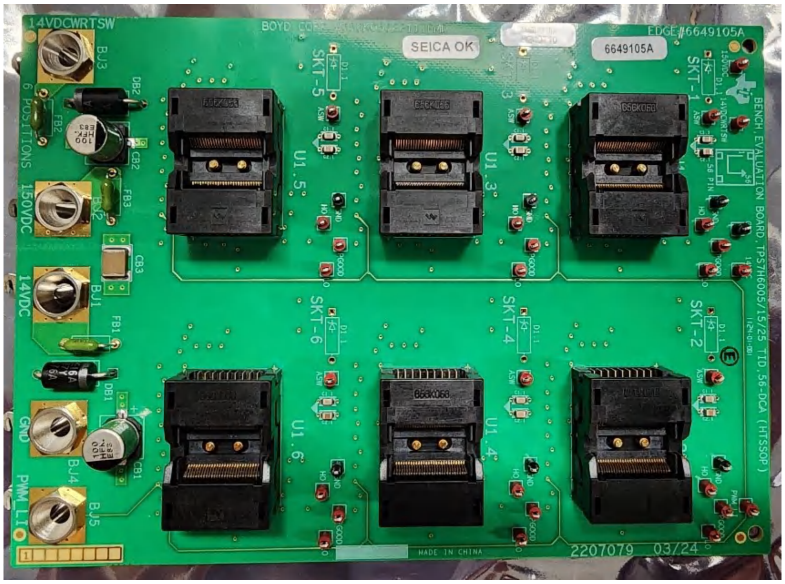


Figure 2-1. HDR TID Hardware

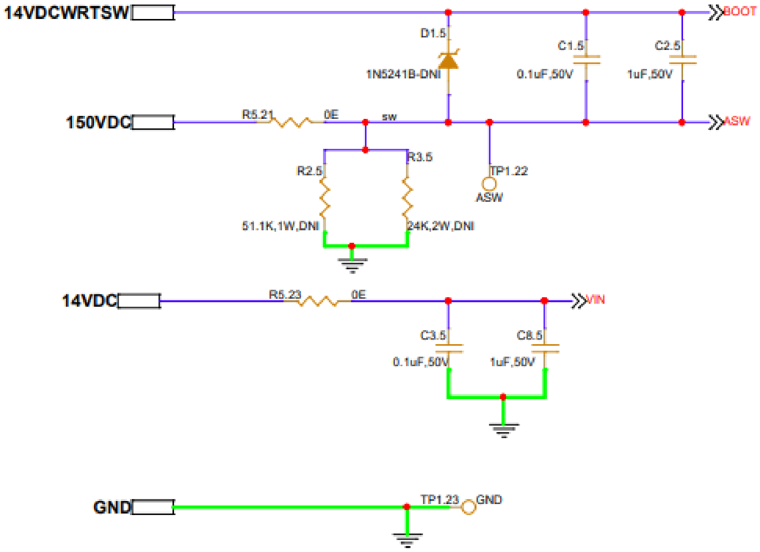


Figure 2-2. Supplies and GND HDR TID Bias Diagram

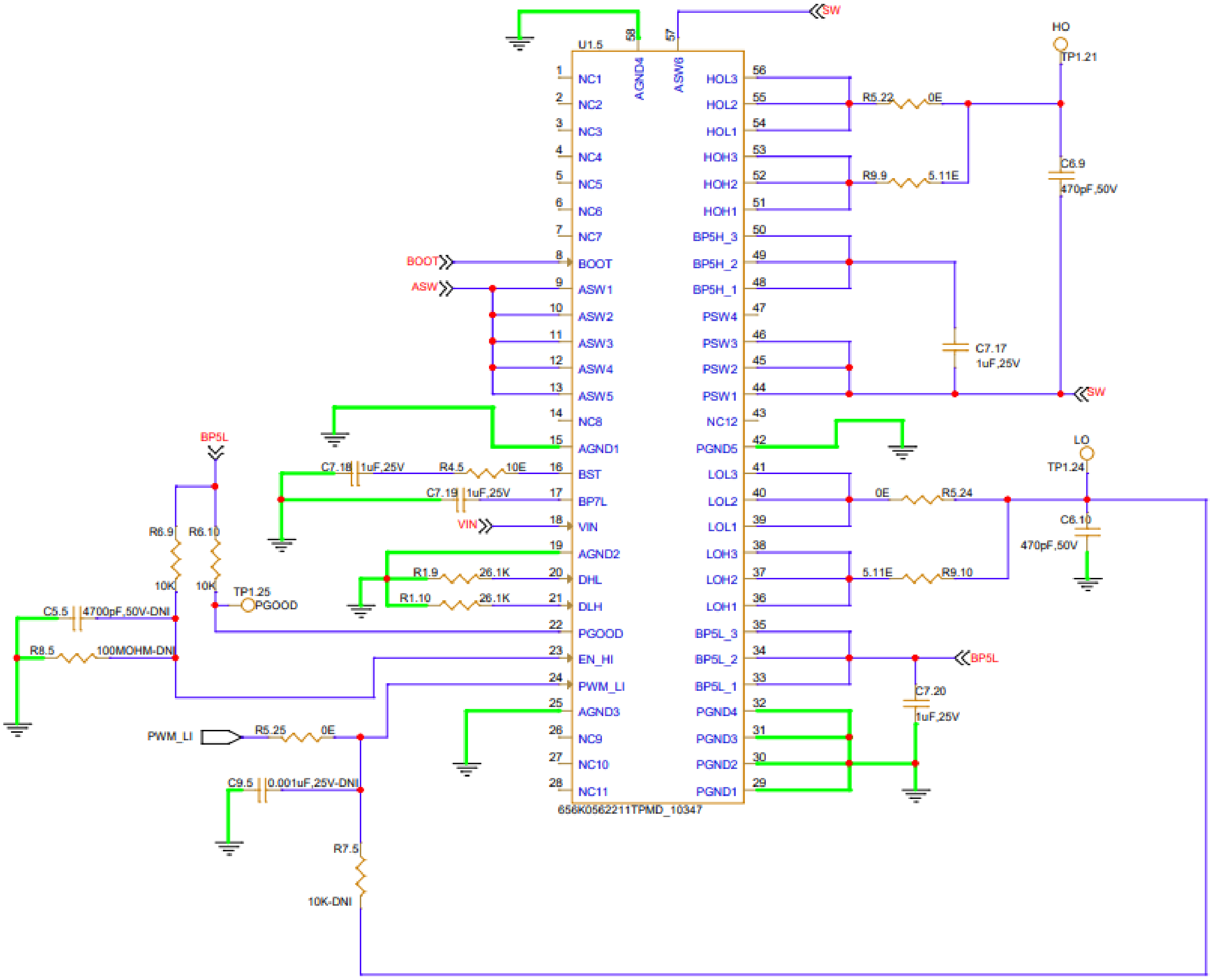


Figure 2-3. HDR TID Bias Diagram

2.4 Test Configuration and Conditions

HDR devices were stressed up to 100 krad (Si) for biased and unbiased conditions.

Table 2-2. HDR Biased Device Information

Total Samples: 6 units + 1 control		
Exposure Levels:		
Control	50krad (Si)	100krad (Si)
72	59, 60, 61	63, 64, 65

Table 2-3. HDR Unbiased Device Information

Total Samples: 6 units + 1 control		
Exposure Levels:		
Control	50krad (Si)	100krad (Si)
72	66, 67, 68	69, 70, 71

3 TID Characterization Test Results

3.1 TID Characterization Results Summary

The results show that all TPS7H6005-SP devices were fully functional and within specification limits up to 100 krad (Si) HDR. Overall the TPS7H6005-SP show a strong degree of hardness to TID HDR exposure levels at 100 krad (Si) under bias & unbiased conditions. Performance is measured based on the difference between pre- and post-irradiation with respect to SMD electrical minimum and maximum specification. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased. (see Section 3.2 for the electrical parameters). Note that test numbers are listed only for parameters tested post-TID.

See Appendix: HDR TID Report for HDR report.

3.2 Data Sheet Electrical Parameters

Specifications are at ambient temperature TA = 25°C, VIN = 10 V to 14 V, VBP5L = VBP5H = 5 V, and no load on LOH, LOL, HOH, and HOL (unless otherwise noted).

Table 3-1. TPS7H6005-SP Data Sheet Electrical Parameters

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
SUPPLY CURRENTS							
I_{QLS}	Low-side quiescent current	VIN = 12V, BOOT = 10V	MODE = PWM, EN = 0V		6.8	mA	35.0, 36.0, 37.0
			MODE = IIM LI = HI = 0V		8		35.2, 36.2, 37.2
I_{QHS}	High-side quiescent current	VIN = 12V, BOOT = 10V	MODE = PWM EN = 0V		6.3	mA	35.1, 36.1, 37.1
			MODE = IIM LI = HI = 0V		6.3		35.3, 36.3, 37.3
I_{OP_LS}	Low-side operating current	MODE = PWM, no load for HOL and HOH	f = 500kHz		9	mA	35.6, 36.6, 37.6
			f = 1MHz		11		35.8, 36.8, 37.8
			f = 2MHz		16		35.1, 36.1, 37.1
			f = 5MHz		30		35.12, 36.12, 37.12
		MODE = IIM, no load for HOL and HOH	f = 500kHz		9		35.14, 36.14, 37.14
			f = 1MHz		12		35.16, 36.16, 37.16
			f = 2MHz		17		35.18, 36.18, 37.18
			f = 5MHz		30		35.2, 36.2, 37.2
I_{OP_HS}	High-side operating current	MODE = PWM, no load for HOL and HOH	f = 500kHz		6.5	mA	35.7, 36.7, 37.7
			f = 1MHz		8		35.9, 36.9, 37.9
			f = 2MHz		10.5		35.11, 36.11, 37.11
			f = 5MHz		19		35.13, 36.13, 37.13
		MODE = IIM, no load for HOL and HOH	f = 500kHz		6.5		35.15, 36.15, 37.15
			f = 1MHz		8		35.17, 36.17, 37.17
			f = 2MHz		10.5		35.19, 36.19, 37.19
			f = 5MHz		15		35.21, 36.21, 37.21
GATE DRIVER							
V_{OL}	Low-level output voltage	I_{OL} = 100mA			0.15	V	45.0, 46.0, 47.0
BP5x – V_{OH}	High-level output voltage	I_{OH} = 100mA			0.3	V	45.2, 46.2, 47.2
I_{OH}	Peak source current	HOH, LOH = 0V, BP5x = 5V		0.7	2.3	A	50, 50.1, 51, 51.1, 52, 52.1
I_{OL}	Peak sink current	HOL, LOL = 5V, BP5x = 5V		1.6	4.6	A	50.2, 51.2, 52.2
INTERNAL REGULATORS							
V_{BP5L}	Low-side 5V regulator output voltage	C_{BP5L} = 1μF		4.75	5.175	V	60.1, 60.4, 60.7, 60.10, 60.13, 60.16, 60.19, 60.22, 61.1, 61.4, 61.7, 61.1, 61.13, 61.16, 61.19, 61.22, 62.1, 62.4, 62.7, 62.1, 62.13, 62.16, 62.19, 62.22
V_{BP5H}	High-side 5V regulator output voltage	C_{BP5H} = 1μF		4.75	5.175	V	60.2, 60.5, 60.8, 60.11, 60.14, 60.17, 60.2, 60.23, 61.2, 61.5, 61.8, 61.11, 61.14, 61.17, 61.2, 61.23, 62.2, 62.5, 62.8, 62.11, 62.14, 62.17, 62.2, 62.23
V_{BP7L}	7V regulator output voltage	C_{BP7L} = 1μF		6.65	7.35	V	60.0, 60.3, 60.6, 60.9, 60.12, 60.15, 60.18, 60.21, 61.0, 61.3, 61.6, 61.9, 61.12, 61.15, 61.18, 61.21, 61.23, 62.0, 62.3, 62.6, 62.9, 62.12, 62.15, 62.18, 62.21
UNDERVOLTAGE PROTECTION							
$BP5H_R$	BP5H UVLO rising threshold	C_{BP5H} = 1μF		4	4.5	V	85.1, 86.1, 87.1(1)
$BP5H_F$	BP5H UVLO falling threshold	C_{BP5H} = 1μF		3.8	4.3	V	85.2, 86.2, 87.2(1)
$BP5L_R$	BP5L UVLO rising threshold	C_{BP5L} = 1μF		4.	4.5	V	80.1, 81.1, 82.1(1)
$BP5L_F$	BP5L UVLO falling threshold	C_{BP5L} = 1μF		3.8	4.3	V	80.2, 81.2, 82.2(1)
$BP7L_R$	BP7L UVLO rising threshold	C_{BP7L} = 1μF		6.2	6.8	V	80.4, 81.4, 82.4(1)

Table 3-1. TPS7H6005-SP Data Sheet Electrical Parameters (continued)

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
BP7L$_F$	BP7L UVLO falling threshold	C$_{BP7L}$ = 1µF		5.9	6.5	V	80.5, 81.5, 82.5(1)
VIN$_R$	VIN UVLO rising threshold			8	9	V	70.0
VIN$_F$	VIN UVLO falling threshold			7.5	8.5	V	70.1
BOOT$_R$	BOOT UVLO rising threshold			6.6	7.4	V	75.0
BOOT$_F$	BOOT UVLO falling threshold			6.2	7	V	75.1
INPUT PINS							
V$_{IR}$	Input rising edge threshold			1.80	2.65	V	90.0, 91.0, 92.0, 90.3, 91.3, 92.3
V$_{IF}$	Input falling edge threshold			1.15	1.85	V	90.1, 91.1, 92.1, 90.4, 91.4, 92.4
R$_{PD}$	Input pull-down resistance	V = 2.15V applied at input (EN_HI or PWM_LI)		100	400	kΩ	90.6, 90.7, 91.6, 91.7, 92.6, 92.7
PROGRAMMABLE DEAD TIME							
T$_{DLH}$	LO off to HO on dead time	MODE = PWM, LO falling to HO rising (90% to 10%), f ≤ 2MHz	RLH = 3.32kΩ	0	10	ns	95.0, 95.5, 95.1, 96, 96.5, 96.10, 97, 97.5, 97.1
			RLH = 11.8kΩ	8	15.5		95.1, 95.6, 95.11, 96.1, 96.6, 96.11, 97.1, 97.6, 97.11
			RLH = 21kΩ	15.5	24		95.2, 95.7, 95.12, 96.2, 96.7, 96.12, 97.2, 97.7, 97.12
			RLH = 52.3kΩ	36	59		95.3, 95.8, 95.13, 96.3, 96.8, 96.13, 97.3, 97.8, 97.13
			RLH = 105kΩ	74	113.5		95.4, 95.9, 95.14, 96.4, 96.9, 96.14, 97.4, 97.9, 97.14
T$_{DHL}$	HO off to LO on dead time	MODE = PWM, HO falling to LO rising (90% to 10%), f ≤ 2MHz	RHL = 7.87kΩ	0	10	ns	95.19, 95.24, 95.29, 96.19, 96.24, 96.29, 97.19, 97.24, 97.29
			RHL = 13.3kΩ	6	14		95.20, 95.25, 95.30, 96.20, 96.25, 96.30, 97.20, 97.25, 97.30
			RHL = 23.7kΩ	16	24.5		95.21, 95.26, 95.31, 96.21, 96.26, 96.31, 97.21, 97.26, 97.31
			RHL = 57.6kΩ	44	61		95.22, 95.27, 95.32, 96.22, 96.27, 96.32, 97.22, 97.27, 97.32
			RHL = 113kΩ	86	125		95.23, 95.28, 95.33, 96.23, 96.28, 96.33, 97.23, 97.28, 97.33
BOOTSTRAP DIODE SWITCH							
	Bootstrap diode switch parallel resistance	I$_{BST\_SW}$ = 1mA		0.8	1.2	kΩ	100.1, 101.1, 102.1
POWER GOOD							
	Logic-low output	I$_{FLT}$= 1mA			0.4	V	105.0, 106.0, 107.0
	PGOOD internal resistance	BP5L = 5V, BP7L = 7V, VIN = 12V		0.7	1.9	MΩ	105.2, 106.2, 107.2
	Minimum BP5L voltage for valid PGOOD output				2.45	V	105.1, 106.1, 107.1

(1) Tests are only tested in production or SPI test mode.

Table 3-2. TPS7H6005-SP Switching Characteristics

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
t_{LPHL}	LO turnoff propagation delay	MODE = PWM	PWM rising to LOL falling		48	ns	110, 111, 112
		MODE = IIM	LI falling to LOL falling		38	ns	110.3, 110.7, 111.3, 111.7, 112.3, 112.7
t_{LPLH}	LO turnon propagation delay	MODE = IIM	LI rising to LOH rising		38	ns	110.2, 110.6, 111.2, 111.6, 112.2, 112.6
t_{HPHL}	HO turnoff propagation delay	MODE = PWM	PWM falling to HOL falling		50	ns	110.1, 111.1,112.1
		MODE = IIM	HI falling to HOL falling		40		110.5, 110.9, 111.5, 111.9, 112.5, 112.9
t_{HPLH}	HO turnon propagation delay	MODE = IIM	HI rising to HOH rising		40	ns	110.4, 110.8, 111.4, 111.8, 112.4, 112.8
t_{MON}	Delay matching LO on and HO off	MODE = IIM			12	ns	110.12, 111.12, 112.12
t_{MOFF}	Delay matching LO off and HO on	MODE = IIM			4	ns	110.11, 110.13, 111.11, 111.13, 112.11, 112.13
t_{HRC}	HO rise time	C_L = 1000pF	10% to 90%		7.5	ns	115, 116, 117
t_{LRC}	LO rise time				7.5	ns	115.2, 116.2, 117.2
t_{HFC}	HO fall time		90% to 10%		5.5	ns	115.1, 116.1, 117.1
t_{LFC}	LO fall time				5.5	ns	115.3, 116.3, 117.3
t_{PW_IIM}	Minimum input pulse width (turn-on)	MODE = IIM			8	ns	120, 120.2, 120.4, 121, 121.2, 121.4, 122, 122.2, 122.4
$t_{PW\_IIM\_OFF}$	Minimum input pulse width (turn-off)	MODE = IIM			12	ns	120.1, 120.3, 120.5, 121.1, 121.3, 121.5, 122.1, 122.3, 122.5

4 Applicable and Reference Documents

4.1 Applicable Documents

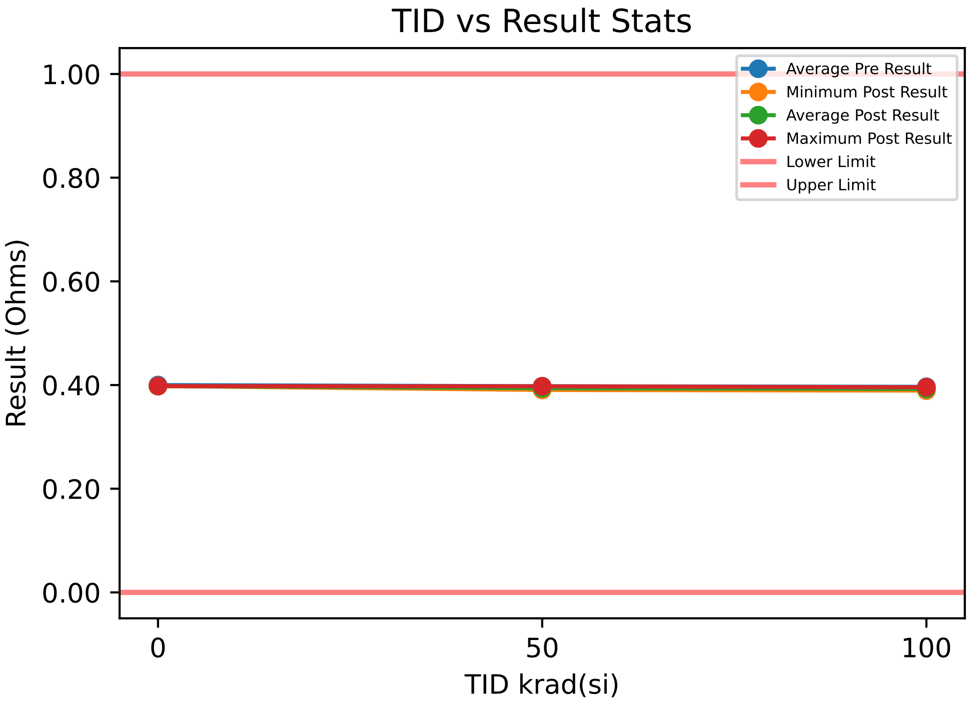
- Texas Instruments, *TPS7H6005-SP Radiation-Hardness-Assured 200-V, 1.3A, 2.5A, Half-Bridge GaN FET Gate Driver*, data sheet.
- Texas Instruments, *TPS7H6005EVM-CVAL Evaluation Module User's Guide*, EVM user's guide.

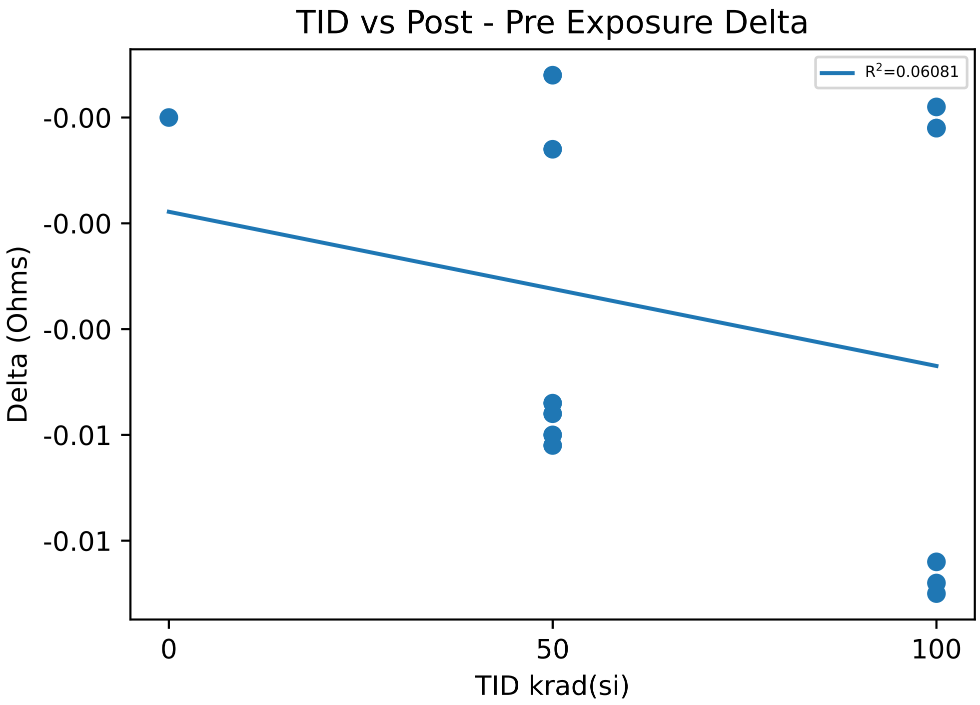
4.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

A Appendix: HDR TID Report

Device Test: 100.0 Bootstrap Diode Switch Resistance VIN_10V





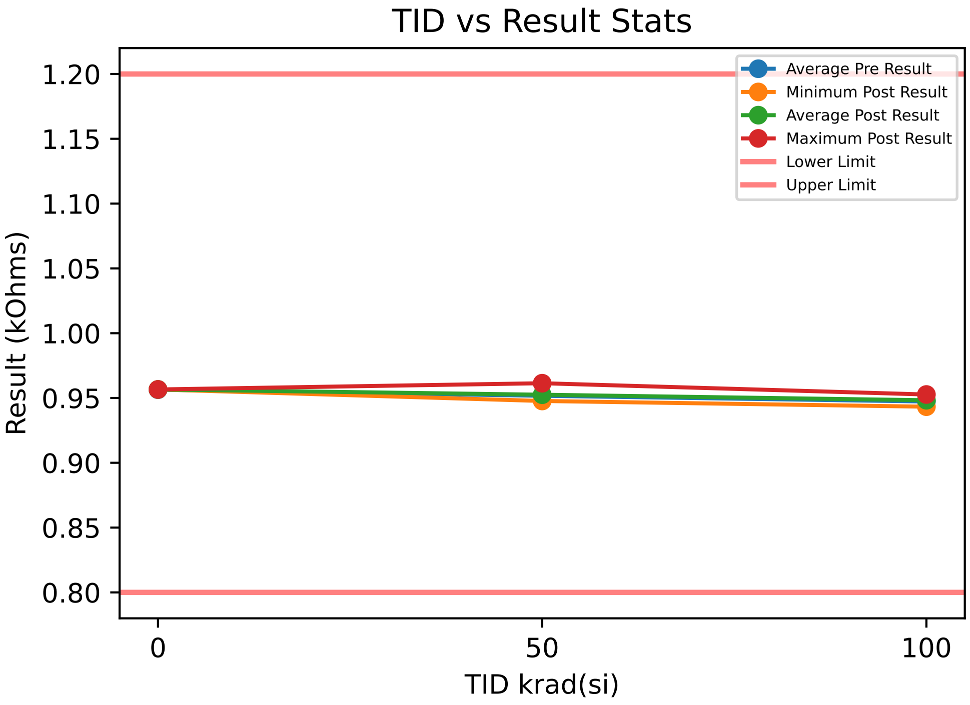
Test Results (Lower Limit = 0.0, Upper Limit = 1.0 (Ohms))

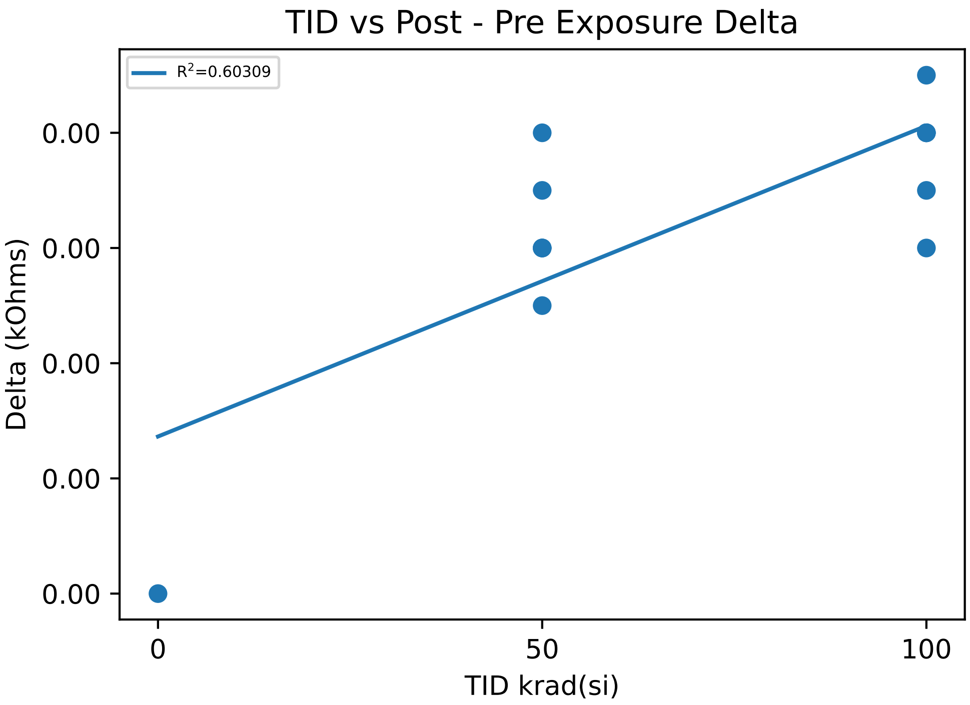
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.3997	0.3974	-0.0023
60	50	Biased	0.3989	0.3938	-0.0051
61	50	Biased	0.3992	0.3976	-0.0016
63	100	Biased	0.3976	0.3957	-0.0019
64	100	Biased	0.3978	0.3957	-0.0021
65	100	Biased	0.396	0.3939	-0.0021
66	50	Unbiased	0.3959	0.3912	-0.0047
67	50	Unbiased	0.3973	0.3925	-0.0048
68	50	Unbiased	0.3954	0.3904	-0.005
69	100	Unbiased	0.3958	0.3893	-0.0065
70	100	Unbiased	0.397	0.3908	-0.0062
71	100	Unbiased	0.3956	0.3892	-0.0064
72	0	Control	0.4	0.398	-0.002

Test Statistics (Ohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.4	0.4	0.4		0.398	0.398	0.398		-0.002	-0.002	-0.002	
50	0.3954	0.39773	0.3997	0.0018096	0.3904	0.39382	0.3976	0.0030792	-0.0051	-0.0039167	-0.0016	0.0015459
100	0.3956	0.39663	0.3978	0.00095847	0.3892	0.39243	0.3957	0.0030474	-0.0065	-0.0042	-0.0019	0.0023766

Device Test: 100.1 Bootstrap Diode Switch Parallel Resistance VIN_10V





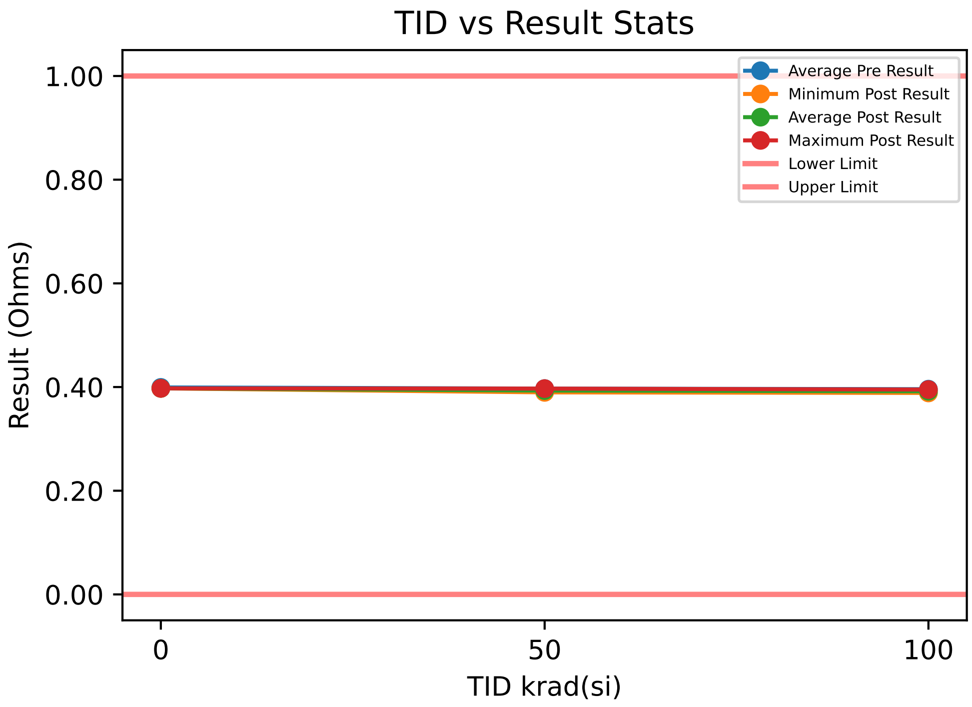
Test Results (Lower Limit = 0.8, Upper Limit = 1.2 (kOhms))

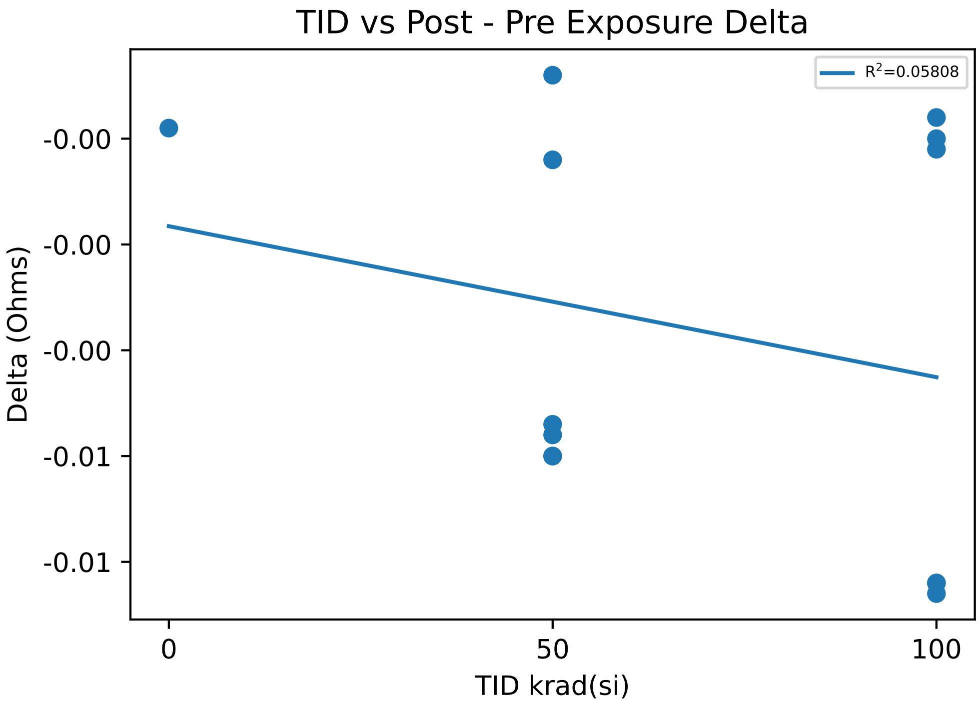
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.9604	0.9614	0.001
60	50	Biased	0.9537	0.9545	0.0008
61	50	Biased	0.9537	0.9545	0.0008
63	100	Biased	0.9467	0.9477	0.001
64	100	Biased	0.9516	0.9527	0.0011
65	100	Biased	0.9487	0.9495	0.0008
66	50	Unbiased	0.9483	0.949	0.0007
67	50	Unbiased	0.9472	0.9481	0.0009
68	50	Unbiased	0.9469	0.9477	0.0008
69	100	Unbiased	0.9472	0.9482	0.001
70	100	Unbiased	0.9424	0.9433	0.0009
71	100	Unbiased	0.9472	0.9482	0.001
72	0	Control	0.9564	0.9566	0.0002

Test Statistics (kOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9564	0.9564	0.9564		0.9566	0.9566	0.9566		0.0002	0.0002	0.0002	
50	0.9469	0.9517	0.9604	0.0052638	0.9477	0.95253	0.9614	0.0053264	0.0007	0.00083333	0.001	0.00010328
100	0.9424	0.9473	0.9516	0.0029947	0.9433	0.94827	0.9527	0.0030389	0.0008	0.00096667	0.0011	0.00010328

Device Test: 101.0 Bootstrap Diode Switch Resistance VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

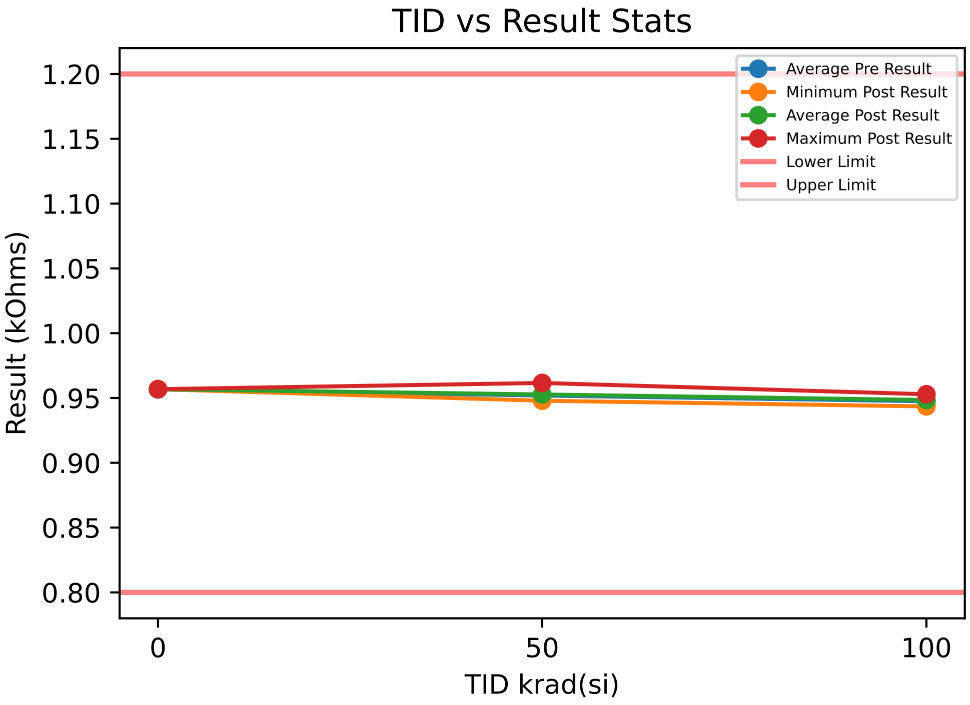
Test Results (Lower Limit = 0.0, Upper Limit = 1.0 (Ohms))

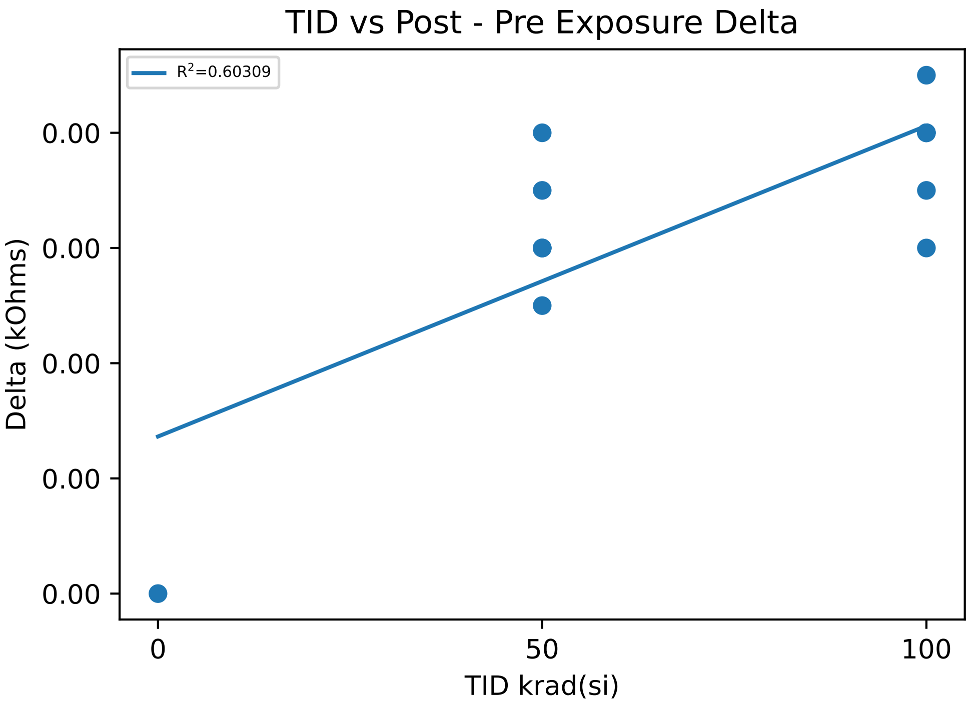
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.399	0.3968	-0.0022
60	50	Biased	0.3982	0.3932	-0.005
61	50	Biased	0.3984	0.397	-0.0014
63	100	Biased	0.3969	0.3951	-0.0018
64	100	Biased	0.3971	0.3951	-0.002
65	100	Biased	0.3953	0.3932	-0.0021
66	50	Unbiased	0.3952	0.3905	-0.0047
67	50	Unbiased	0.3966	0.3918	-0.0048
68	50	Unbiased	0.3947	0.3897	-0.005
69	100	Unbiased	0.395	0.3887	-0.0063
70	100	Unbiased	0.3963	0.3901	-0.0062
71	100	Unbiased	0.3948	0.3886	-0.0062
72	0	Control	0.3993	0.3974	-0.0019

Test Statistics (Ohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3993	0.3993	0.3993		0.3974	0.3974	0.3974		-0.0019	-0.0019	-0.0019	
50	0.3947	0.39702	0.399	0.0017938	0.3897	0.39317	0.397	0.0031271	-0.005	-0.00385	-0.0014	0.0016121
100	0.3948	0.3959	0.3971	0.000998	0.3886	0.3918	0.3951	0.0030489	-0.0063	-0.0041	-0.0018	0.0023392

Device Test: 101.1 Bootstrap Diode Switch Parallel Resistance VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

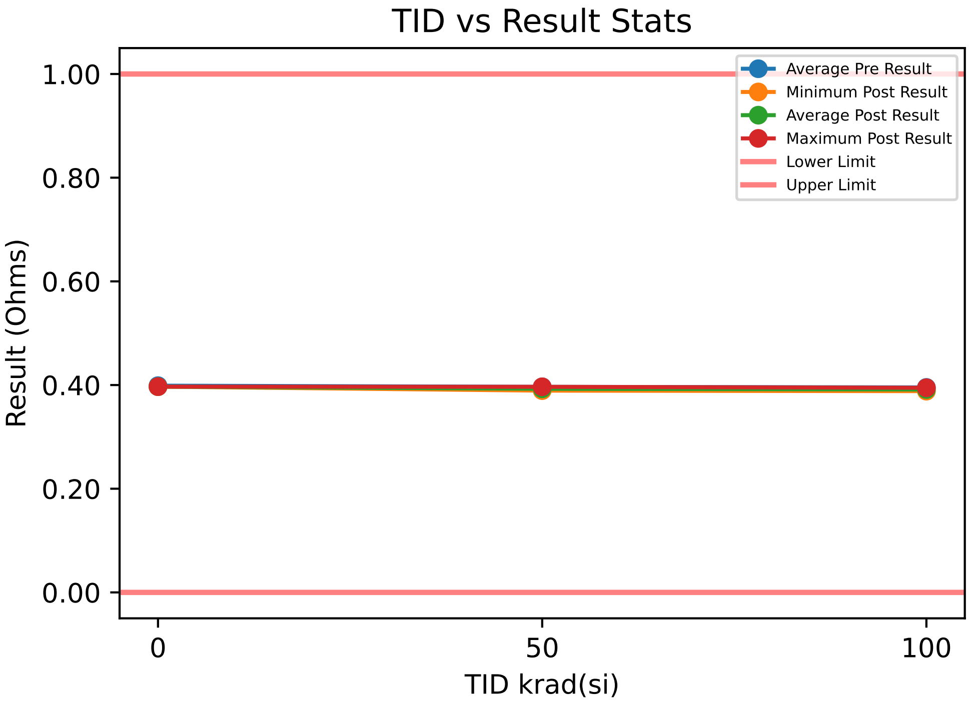
Test Results (Lower Limit = 0.8, Upper Limit = 1.2 (kOhms))

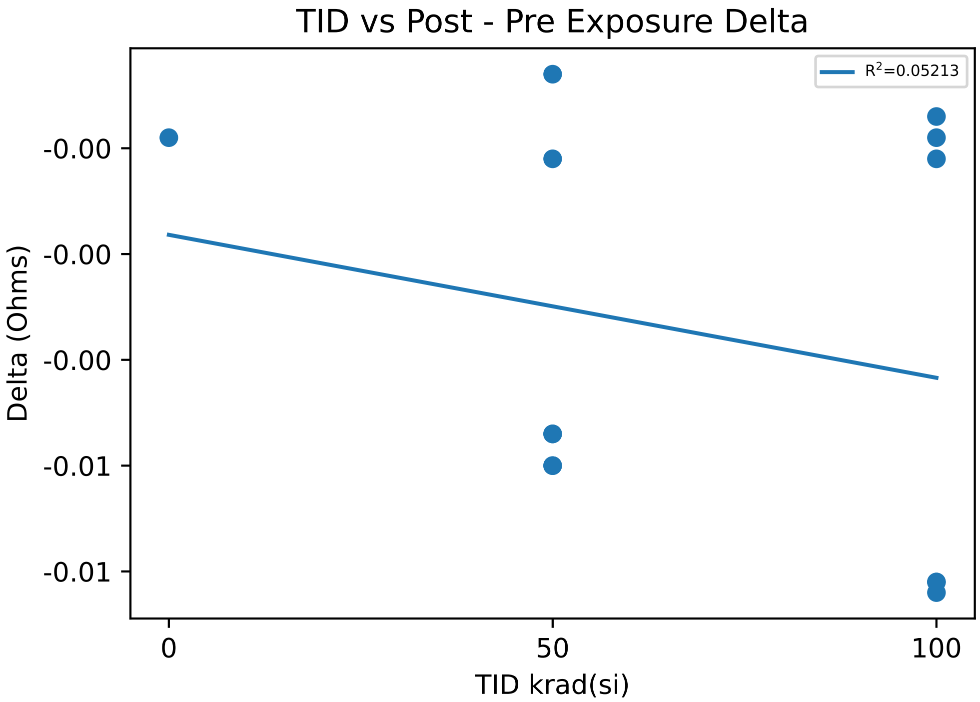
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.9606	0.9616	0.001
60	50	Biased	0.9539	0.9547	0.0008
61	50	Biased	0.9539	0.9547	0.0008
63	100	Biased	0.9469	0.9479	0.001
64	100	Biased	0.9518	0.9529	0.0011
65	100	Biased	0.9489	0.9497	0.0008
66	50	Unbiased	0.9485	0.9492	0.0007
67	50	Unbiased	0.9474	0.9483	0.0009
68	50	Unbiased	0.9471	0.9479	0.0008
69	100	Unbiased	0.9474	0.9484	0.001
70	100	Unbiased	0.9426	0.9435	0.0009
71	100	Unbiased	0.9474	0.9484	0.001
72	0	Control	0.9566	0.9568	0.0002

Test Statistics (kOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9566	0.9566	0.9566		0.9568	0.9568	0.9568		0.0002	0.0002	0.0002	
50	0.9471	0.9519	0.9606	0.0052638	0.9479	0.95273	0.9616	0.0053264	0.0007	0.00083333	0.001	0.00010328
100	0.9426	0.9475	0.9518	0.0029947	0.9435	0.94847	0.9529	0.0030389	0.0008	0.00096667	0.0011	0.00010328

Device Test: 102.0 Bootstrap Diode Switch Resistance VIN_14V





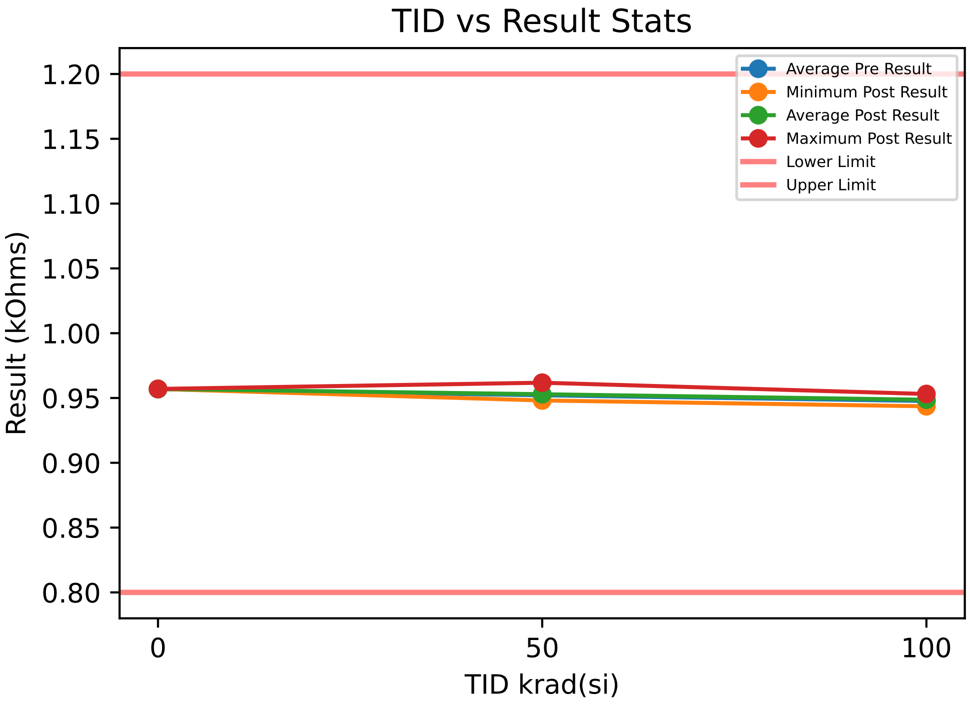
Test Results (Lower Limit = 0.0, Upper Limit = 1.0 (Ohms))

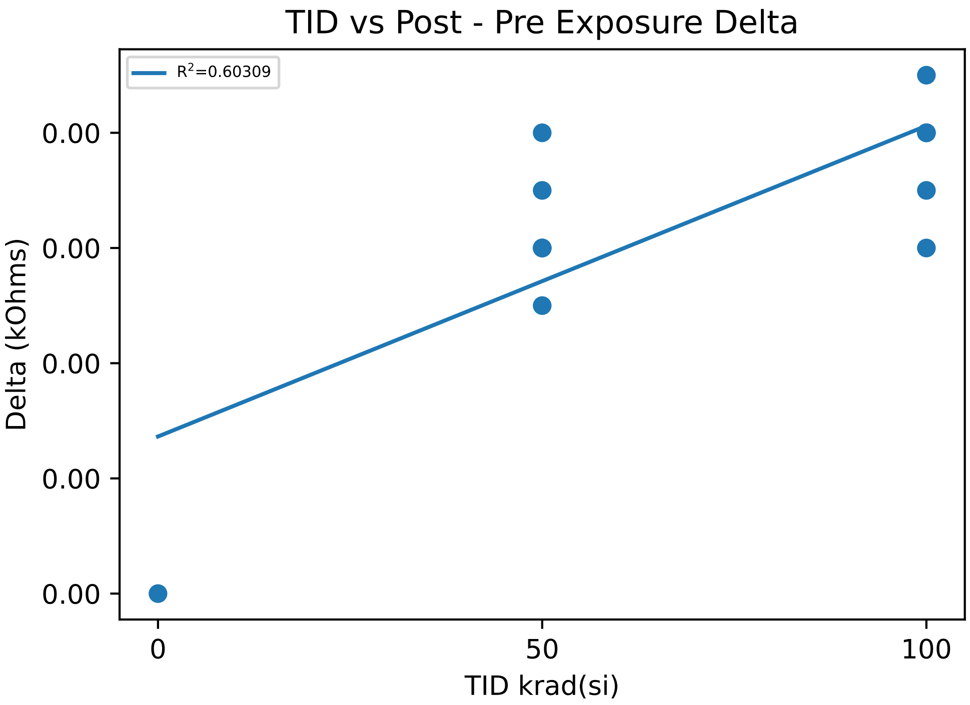
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.3985	0.3964	-0.0021
60	50	Biased	0.3977	0.3927	-0.005
61	50	Biased	0.3979	0.3966	-0.0013
63	100	Biased	0.3964	0.3947	-0.0017
64	100	Biased	0.3966	0.3947	-0.0019
65	100	Biased	0.3948	0.3927	-0.0021
66	50	Unbiased	0.3947	0.39	-0.0047
67	50	Unbiased	0.3961	0.3914	-0.0047
68	50	Unbiased	0.3942	0.3892	-0.005
69	100	Unbiased	0.3945	0.3883	-0.0062
70	100	Unbiased	0.3958	0.3897	-0.0061
71	100	Unbiased	0.3943	0.3882	-0.0061
72	0	Control	0.3988	0.3969	-0.0019

Test Statistics (Ohms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3988	0.3988	0.3988		0.3969	0.3969	0.3969		-0.0019	-0.0019	-0.0019	
50	0.3942	0.39652	0.3985	0.0017938	0.3892	0.39272	0.3966	0.0031663	-0.005	-0.0038	-0.0013	0.0016517
100	0.3943	0.3954	0.3966	0.000998	0.3882	0.39138	0.3947	0.00304	-0.0062	-0.0040167	-0.0017	0.0023224

Device Test: 102.1 Bootstrap Diode Switch Parallel Resistance VIN_14V





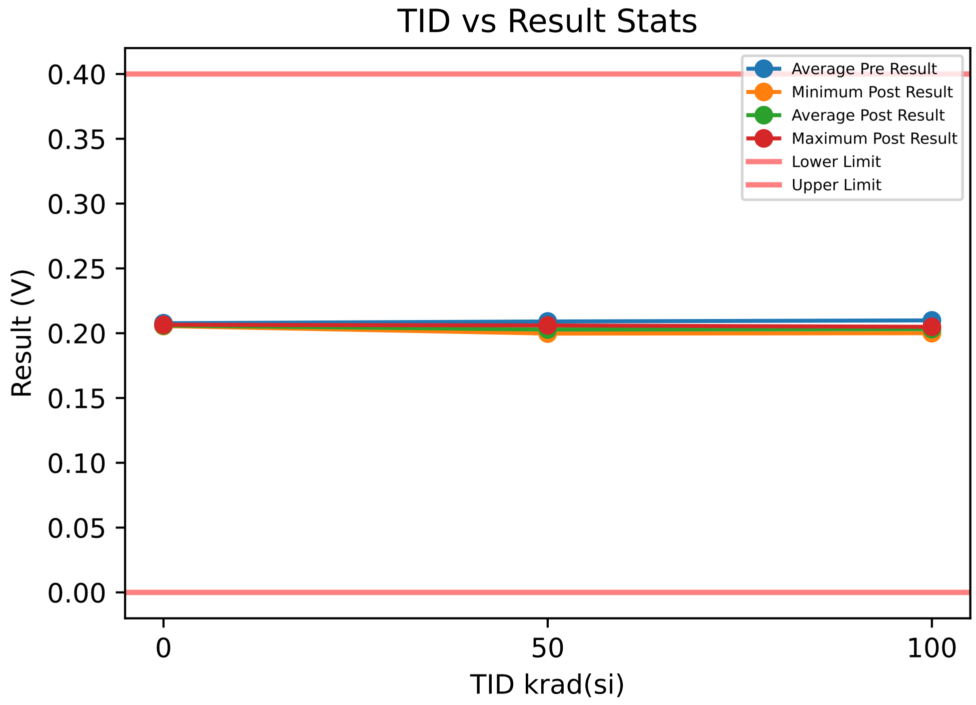
Test Results (Lower Limit = 0.8, Upper Limit = 1.2 (kOhms))

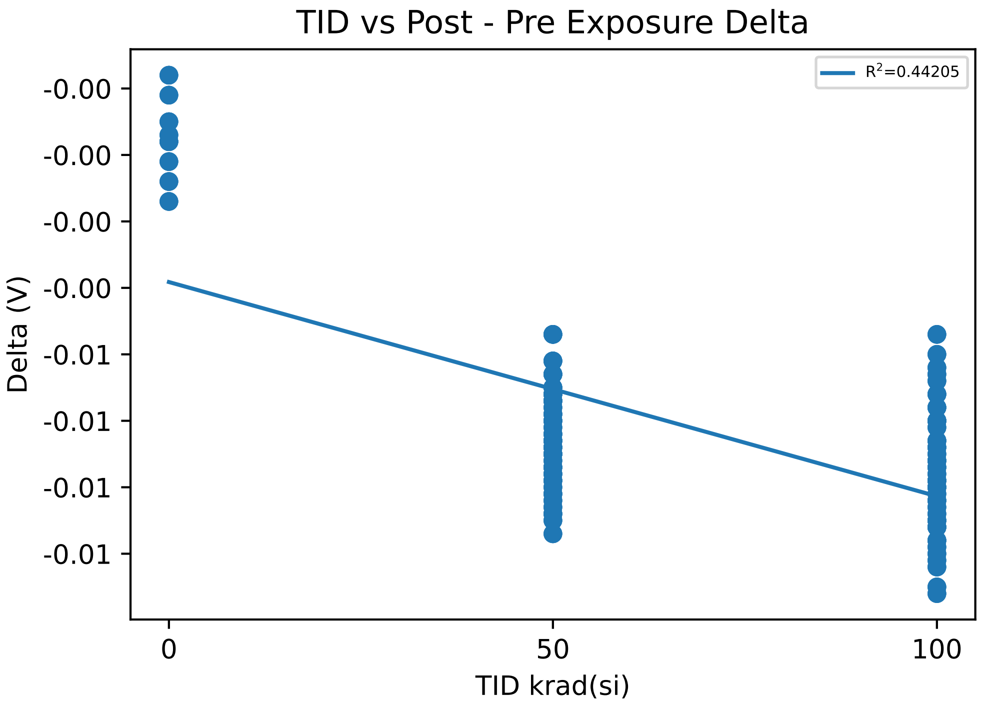
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.9608	0.9618	0.001
60	50	Biased	0.9541	0.9549	0.0008
61	50	Biased	0.9541	0.9548	0.0007
63	100	Biased	0.9471	0.9481	0.001
64	100	Biased	0.952	0.9531	0.0011
65	100	Biased	0.9491	0.9499	0.0008
66	50	Unbiased	0.9486	0.9494	0.0008
67	50	Unbiased	0.9476	0.9485	0.0009
68	50	Unbiased	0.9473	0.9481	0.0008
69	100	Unbiased	0.9476	0.9486	0.001
70	100	Unbiased	0.9427	0.9436	0.0009
71	100	Unbiased	0.9476	0.9486	0.001
72	0	Control	0.9568	0.957	0.0002

Test Statistics (kOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9568	0.9568	0.9568		0.957	0.957	0.957		0.0002	0.0002	0.0002	
50	0.9473	0.95208	0.9608	0.0052769	0.9481	0.95292	0.9618	0.0053192	0.0007	0.00083333	0.001	0.00010328
100	0.9427	0.94768	0.952	0.0030275	0.9436	0.94865	0.9531	0.0030716	0.0008	0.00096667	0.0011	0.00010328

Device Test: 105.0 PGOOD Logic Low Outupt


TID vs Result Stats


TID vs Post - Pre Exposure Delta

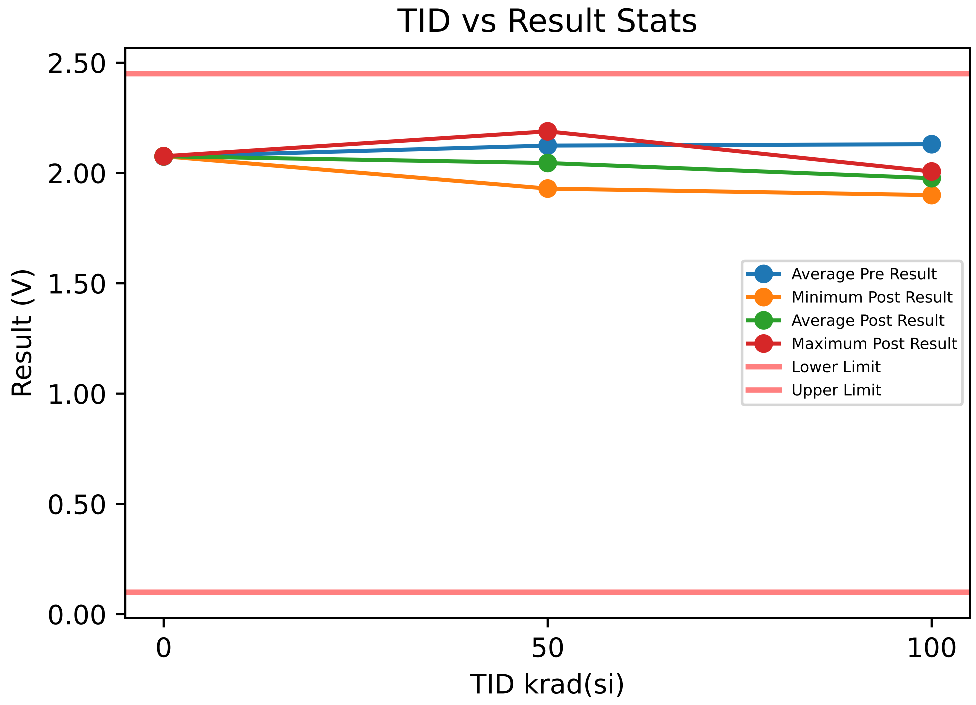
Test Results (Lower Limit = 0.0, Upper Limit = 0.4 (V))

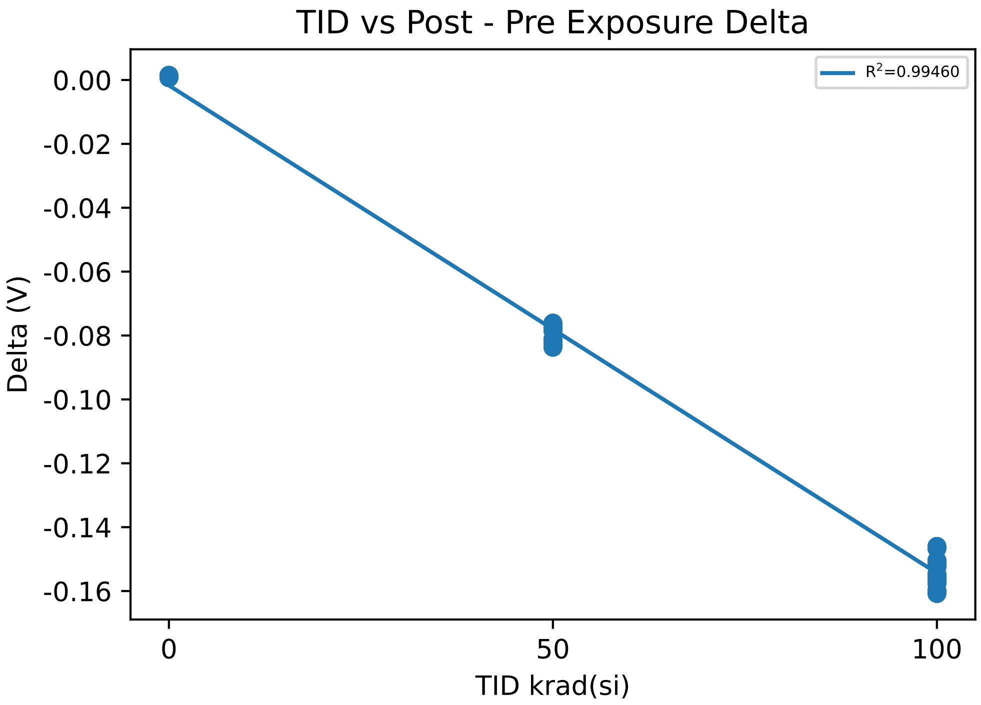
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.2064	0.2006	-0.0058
60	50	Biased	0.2075	0.2007	-0.0068
61	50	Biased	0.2068	0.2012	-0.0056
63	100	Biased	0.2087	0.2029	-0.0058
64	100	Biased	0.2078	0.2009	-0.0069
65	100	Biased	0.2109	0.2049	-0.006
66	50	Unbiased	0.2123	0.206	-0.0063
67	50	Unbiased	0.2122	0.2057	-0.0065
68	50	Unbiased	0.2122	0.2058	-0.0064
69	100	Unbiased	0.2114	0.2038	-0.0076
70	100	Unbiased	0.2121	0.2046	-0.0075
71	100	Unbiased	0.2116	0.2047	-0.0069
72	0	Control	0.2082	0.2065	-0.0017

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2082	0.2082	0.2082		0.2065	0.2065	0.2065		-0.0017	-0.0017	-0.0017	
50	0.2064	0.20957	0.2123	0.0029426	0.2006	0.20333	0.206	0.0027478	-0.0068	-0.0062333	-0.0056	0.00045019
100	0.2078	0.21042	0.2121	0.0017452	0.2009	0.20363	0.2049	0.0015306	-0.0076	-0.0067833	-0.0058	0.00074677

Device Test: 105.1 Min BP5L for Valid PGOOD


TID vs Result Stats


TID vs Post - Pre Exposure Delta

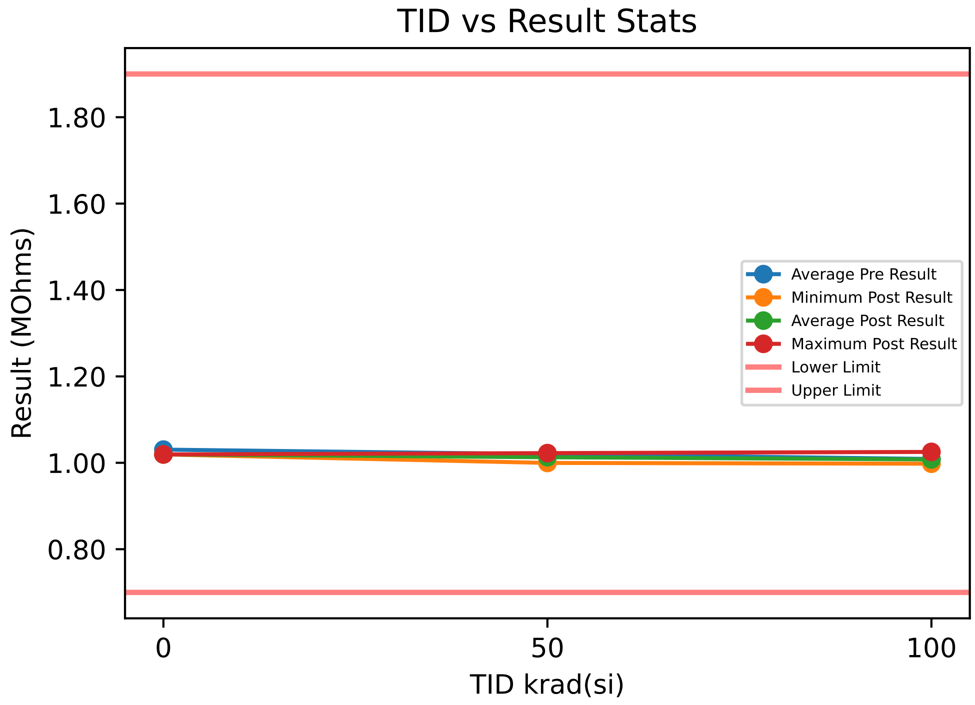
Test Results (Lower Limit = 0.1, Upper Limit = 2.45 (V))

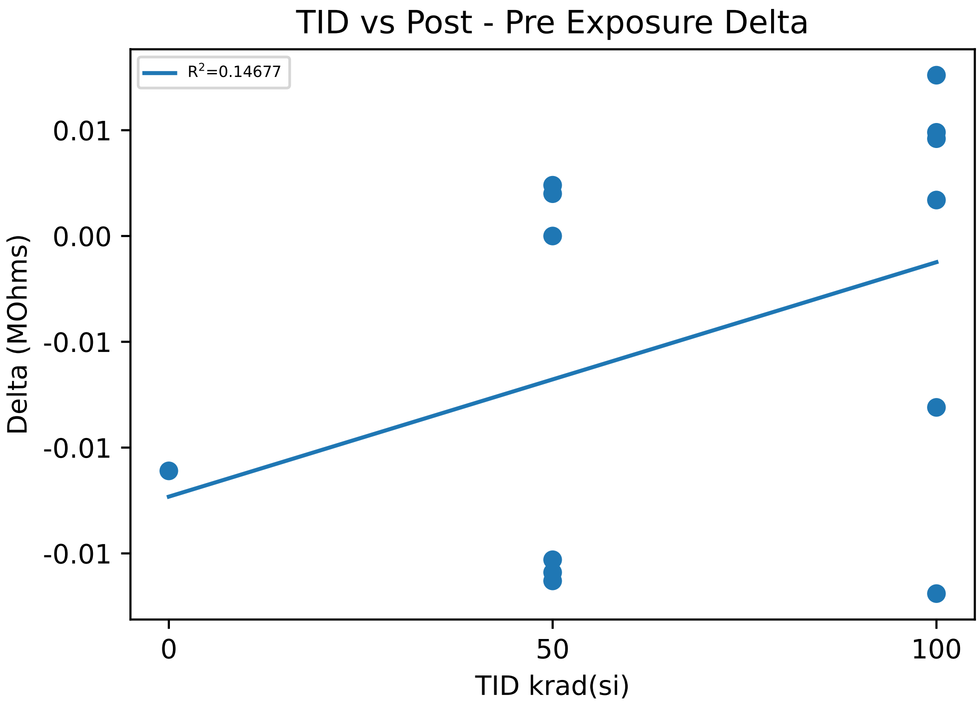
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.0106	1.9295	-0.0811
60	50	Biased	2.0397	1.9631	-0.0766
61	50	Biased	2.0784	2.0005	-0.0779
63	100	Biased	2.1497	1.9928	-0.1569
64	100	Biased	2.0553	1.8999	-0.1554
65	100	Biased	2.1214	1.9691	-0.1523
66	50	Unbiased	2.2716	2.1884	-0.0832
67	50	Unbiased	2.1208	2.0428	-0.078
68	50	Unbiased	2.2232	2.1402	-0.083
69	100	Unbiased	2.1383	1.9878	-0.1505
70	100	Unbiased	2.1667	2.0067	-0.16
71	100	Unbiased	2.149	2.0025	-0.1465
72	0	Control	2.0745	2.0759	0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0745	2.0745	2.0745		2.0759	2.0759	2.0759		0.0014	0.0014	0.0014	
50	2.0106	2.124	2.2716	0.10362	1.9295	2.0441	2.1884	0.10164	-0.0832	-0.079967	-0.0766	0.002843
100	2.0553	2.1301	2.1667	0.039545	1.8999	1.9765	2.0067	0.039759	-0.16	-0.1536	-0.1465	0.0048332

Device Test: 105.2 PGOOD Internal Resistance VIN_10V





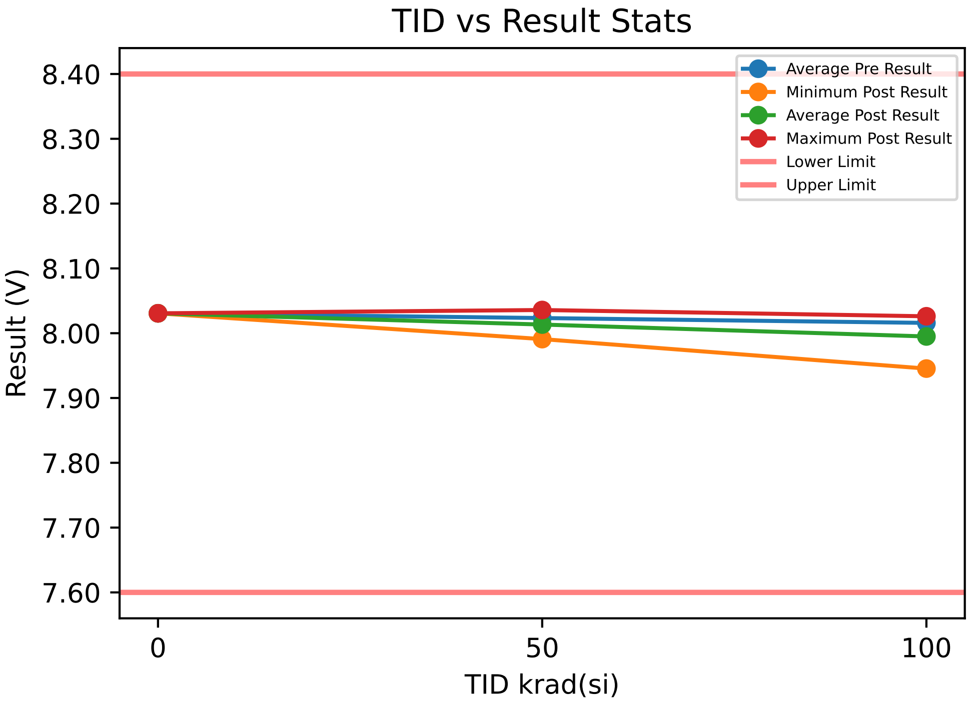
Test Results (Lower Limit = 0.7, Upper Limit = 1.9 (MOhms))

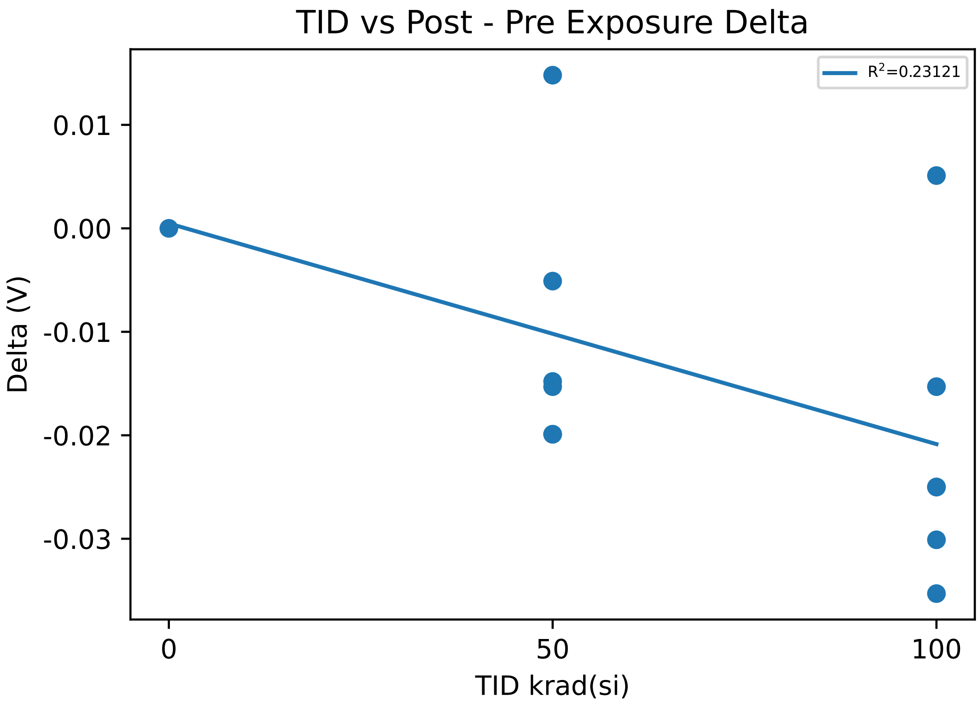
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.02	1.0224	0.0024
60	50	Biased	1.0326	1.0173	-0.0153
61	50	Biased	1.0201	1.0221	0.002
63	100	Biased	1.0084	1.013	0.0046
64	100	Biased	1.0333	1.0252	-0.0081
65	100	Biased	1.0024	1.0041	0.0017
66	50	Unbiased	1.0156	0.9997	-0.0159
67	50	Unbiased	1.0116	1.0116	0
68	50	Unbiased	1.0203	1.004	-0.0163
69	100	Unbiased	0.9978	1.0027	0.0049
70	100	Unbiased	1.0148	0.9979	-0.0169
71	100	Unbiased	0.9966	1.0042	0.0076
72	0	Control	1.0305	1.0194	-0.0111

Test Statistics (MOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0305	1.0305	1.0305		1.0194	1.0194	1.0194		-0.0111	-0.0111	-0.0111	
50	1.0116	1.02	1.0326	0.0070537	0.9997	1.0129	1.0224	0.0094802	-0.0163	-0.0071833	0.0024	0.0095158
100	0.9966	1.0089	1.0333	0.013763	0.9979	1.0078	1.0252	0.0098026	-0.0169	-0.0010333	0.0076	0.0094935

Device Test: 105.3 PGOOD Test Mode Entry V VIN_10V





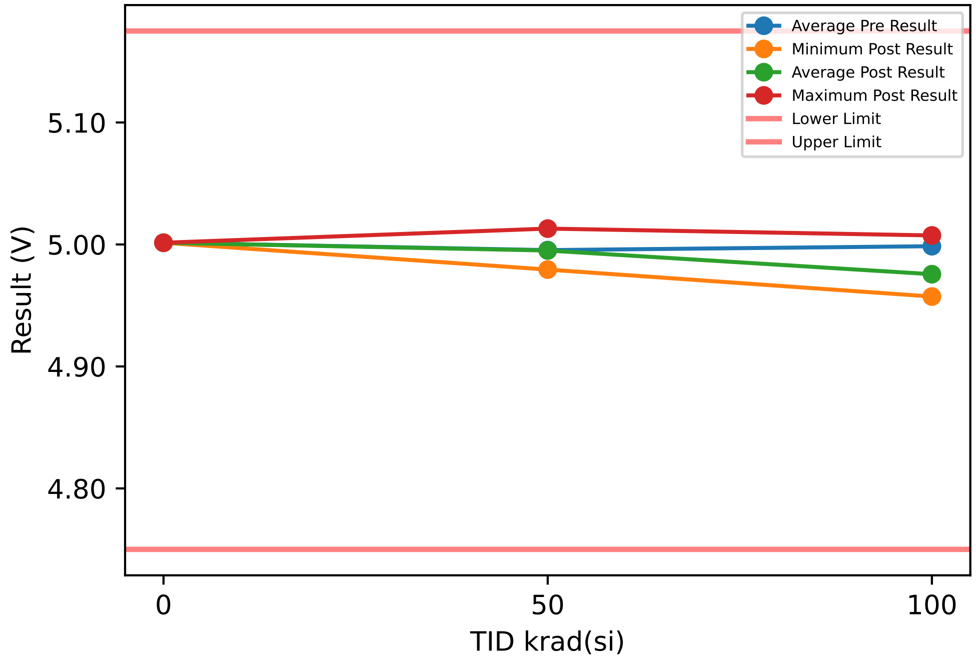
Test Results (Lower Limit = 7.6, Upper Limit = 8.4 (V))

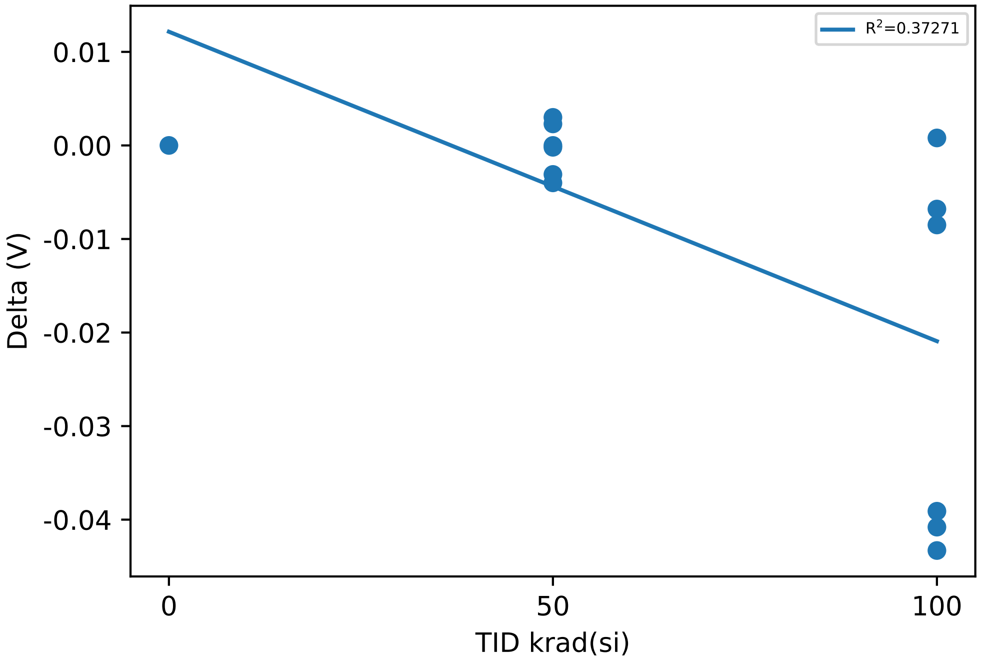
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	8.0307	8.0159	-0.0148
60	50	Biased	8.021	8.0358	0.0148
61	50	Biased	8.046	8.0307	-0.0153
63	100	Biased	8.021	7.9909	-0.0301
64	100	Biased	8.0261	8.0108	-0.0153
65	100	Biased	8.0108	7.9858	-0.025
66	50	Unbiased	8.0108	7.9909	-0.0199
67	50	Unbiased	8.0358	8.0159	-0.0199
68	50	Unbiased	7.996	7.9909	-0.0051
69	100	Unbiased	8.021	8.0261	0.0051
70	100	Unbiased	7.9807	7.9454	-0.0353
71	100	Unbiased	8.0358	8.0108	-0.025
72	0	Control	8.0307	8.0307	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0307	8.0307	8.0307		8.0307	8.0307	8.0307		0	0	0	
50	7.996	8.0234	8.046	0.018073	7.9909	8.0134	8.0358	0.01911	-0.0199	-0.010033	0.0148	0.013313
100	7.9807	8.0159	8.0358	0.019064	7.9454	7.995	8.0261	0.028383	-0.0353	-0.020933	0.0051	0.014373

Device Test: 105.4 LMUX Output High Voltage Level VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

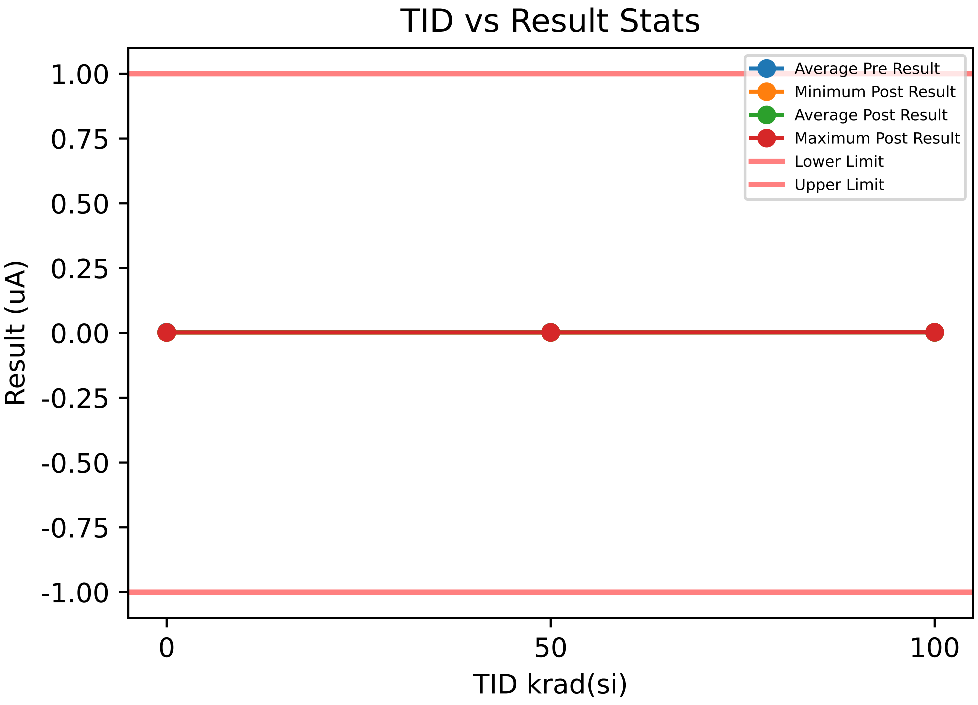
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

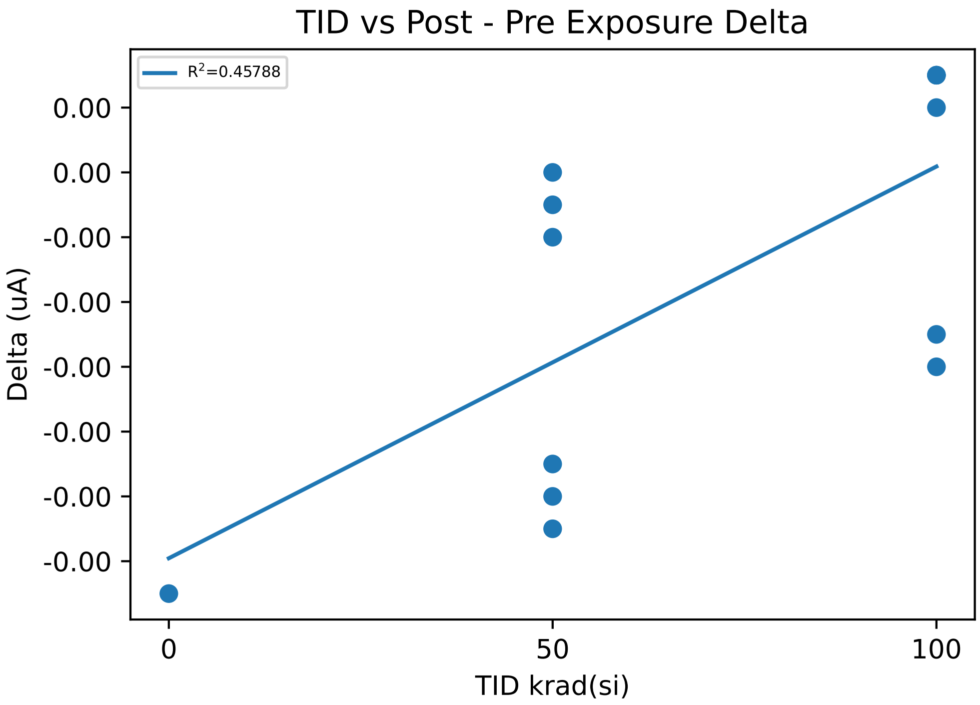
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5	4.9998	-0.0002
60	50	Biased	4.9812	4.9842	0.003
61	50	Biased	5.0052	5.0075	0.0023
63	100	Biased	5	4.9609	-0.0391
64	100	Biased	4.9875	4.979	-0.0085
65	100	Biased	4.9981	4.9573	-0.0408
66	50	Unbiased	4.9825	4.9794	-0.0031
67	50	Unbiased	4.9863	4.9863	0
68	50	Unbiased	5.017	5.013	-0.004
69	100	Unbiased	5.0142	5.0074	-0.0068
70	100	Unbiased	4.9897	4.9905	0.0008
71	100	Unbiased	5.0019	4.9586	-0.0433
72	0	Control	5.0014	5.0014	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0014	5.0014	5.0014		5.0014	5.0014	5.0014		0	0	0	
50	4.9812	4.9954	5.017	0.014385	4.9794	4.995	5.013	0.013704	-0.004	-0.00033333	0.003	0.0028026
100	4.9875	4.9986	5.0142	0.0095799	4.9573	4.9756	5.0074	0.02042	-0.0433	-0.02295	0.0008	0.020136

Device Test: 105.5 LMUX Output High Leakage Current VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

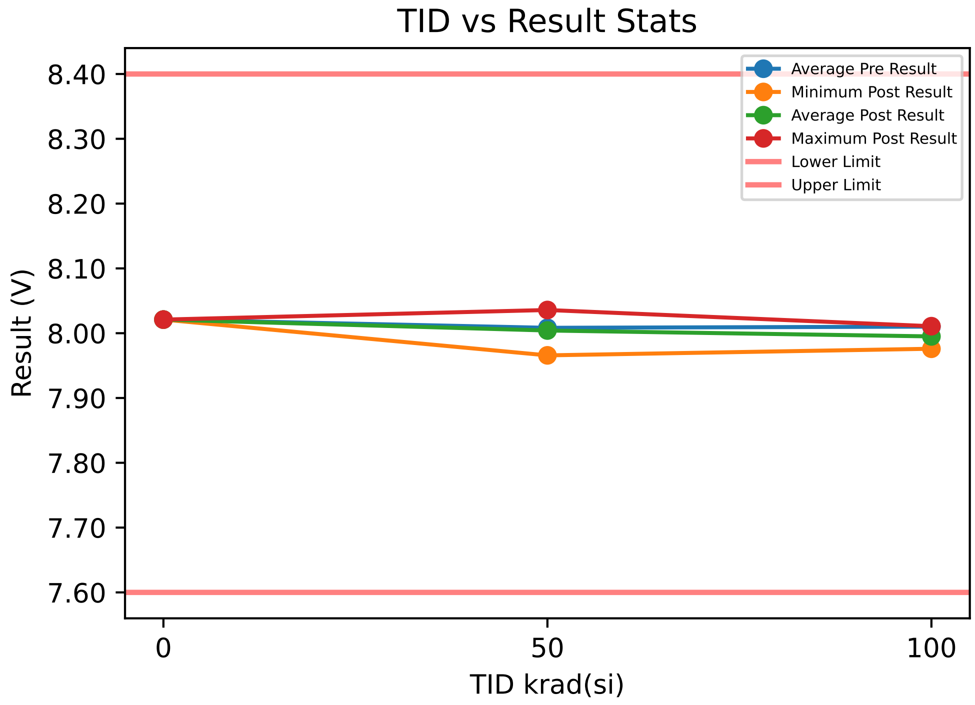
Test Results (Lower Limit = -1.0, Upper Limit = 1.0 (uA))

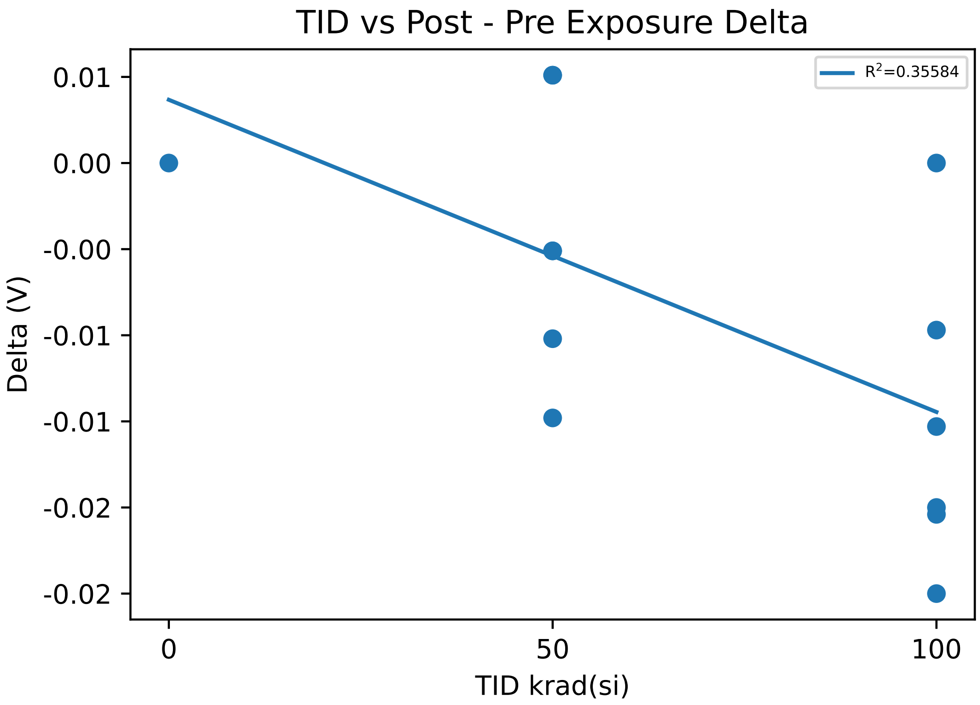
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.002	0.002	0
60	50	Biased	0.0029	0.002	-0.0009
61	50	Biased	0.0021	0.0019	-0.0002
63	100	Biased	0.002	0.0023	0.0003
64	100	Biased	0.0029	0.0023	-0.0006
65	100	Biased	0.002	0.0023	0.0003
66	50	Unbiased	0.0031	0.002	-0.0011
67	50	Unbiased	0.0021	0.002	-0.0001
68	50	Unbiased	0.0029	0.0019	-0.001
69	100	Unbiased	0.0021	0.0024	0.0003
70	100	Unbiased	0.003	0.0025	-0.0005
71	100	Unbiased	0.0021	0.0023	0.0002
72	0	Control	0.0032	0.0019	-0.0013

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0032	0.0032	0.0032		0.0019	0.0019	0.0019		-0.0013	-0.0013	-0.0013	
50	0.002	0.0025167	0.0031	0.00049967	0.0019	0.0019667	0.002	5.164e-05	-0.0011	-0.00055	0	0.000501
100	0.002	0.00235	0.003	0.00046797	0.0023	0.00235	0.0025	8.3666e-05	-0.0006	0	0.0003	0.00042895

Device Test: 105.6 HEN_TST Test Mode Entry V VIN_10V





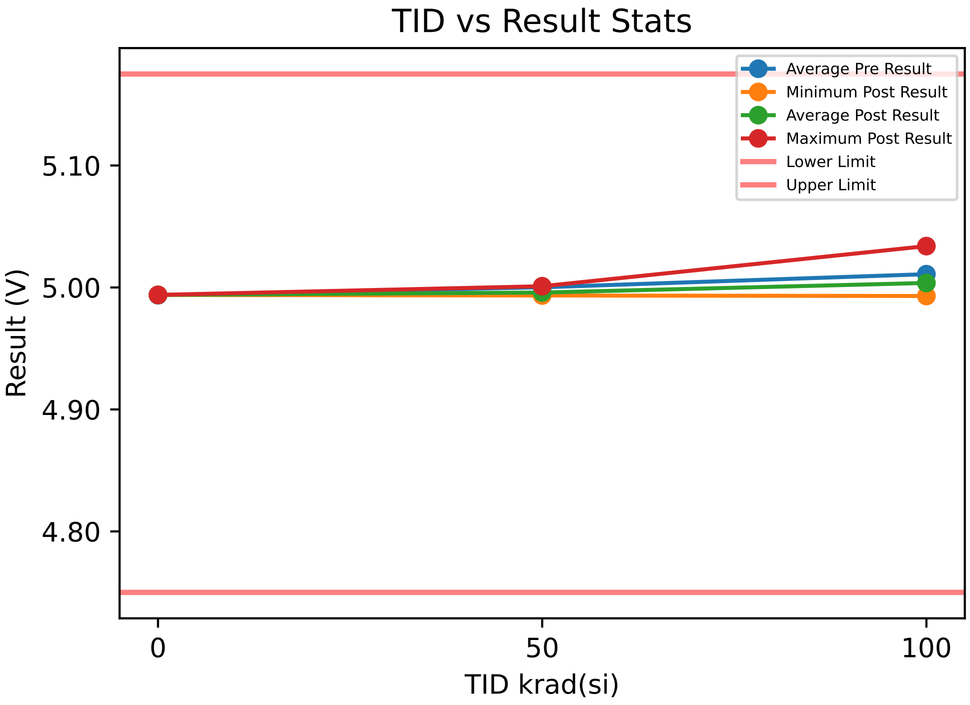
Test Results (Lower Limit = 7.6,
Upper Limit = 8.4 (V))

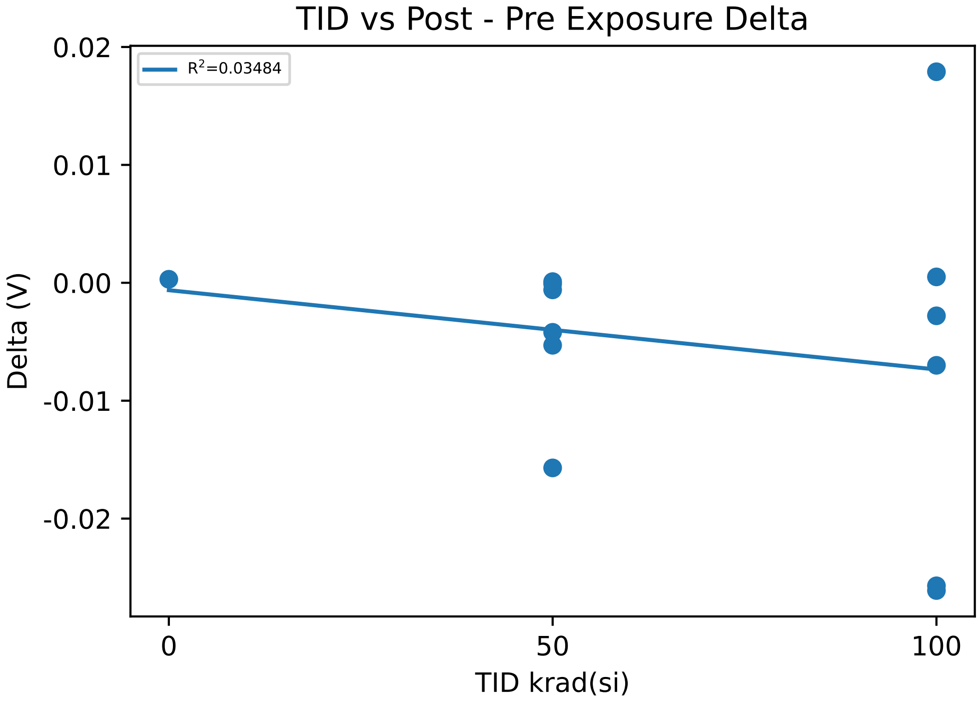
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	8.0108	7.996	-0.0148
60	50	Biased	8.0057	8.0108	0.0051
61	50	Biased	8.0159	8.0108	-0.0051
63	100	Biased	8.0108	8.0108	0
64	100	Biased	7.996	7.9807	-0.0153
65	100	Biased	7.996	7.976	-0.02
66	50	Unbiased	8.0159	8.0057	-0.0102
67	50	Unbiased	7.9607	7.9658	0.0051
68	50	Unbiased	8.0409	8.0358	-0.0051
69	100	Unbiased	8.021	7.996	-0.025
70	100	Unbiased	8.0261	8.0057	-0.0204
71	100	Unbiased	8.0108	8.0011	-0.0097
72	0	Control	8.021	8.021	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.021	8.021	8.021		8.021	8.021	8.021		0	0	0	
50	7.9607	8.0083	8.0409	0.026295	7.9658	8.0042	8.0358	0.022933	-0.0148	-0.0041667	0.0051	0.0080368
100	7.996	8.0101	8.0261	0.012437	7.976	7.995	8.0108	0.013913	-0.025	-0.015067	0	0.0090257

Device Test: 105.7 HMUX Output High Voltage Level VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

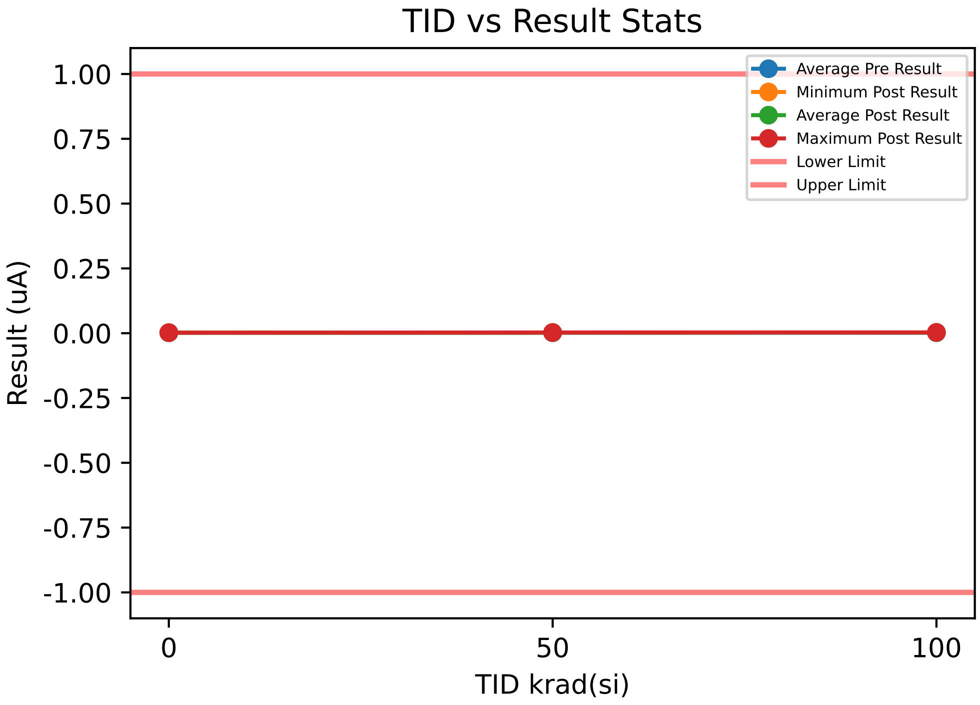
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0013	4.996	-0.0053
60	50	Biased	4.994	4.9934	-0.0006
61	50	Biased	5.0008	4.9966	-0.0042
63	100	Biased	4.9966	4.9938	-0.0028
64	100	Biased	5.0198	4.9941	-0.0257
65	100	Biased	5.0199	5.0129	-0.007
66	50	Unbiased	4.9942	4.9943	0.0001
67	50	Unbiased	4.9937	4.9936	-0.0001
68	50	Unbiased	5.0167	5.001	-0.0157
69	100	Unbiased	5.0191	4.993	-0.0261
70	100	Unbiased	4.9939	4.9944	0.0005
71	100	Unbiased	5.016	5.0339	0.0179
72	0	Control	4.9936	4.9939	0.0003

Test Statistics (V)

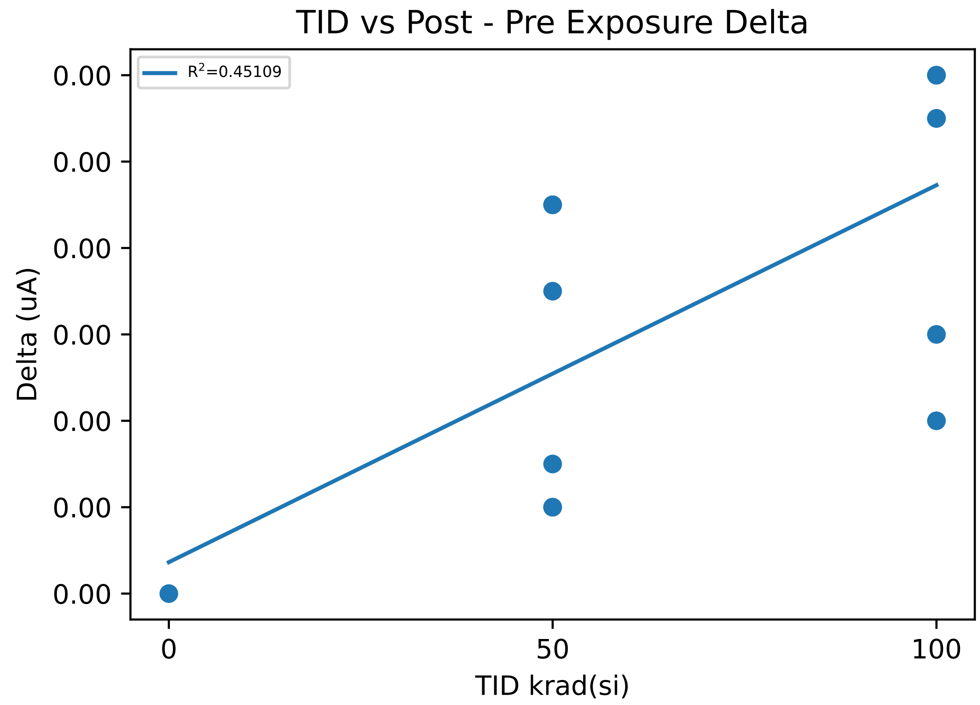
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9936	4.9936	4.9936		4.9939	4.9939	4.9939		0.0003	0.0003	0.0003	
50	4.9937	5.0001	5.0167	0.0088371	4.9934	4.9958	5.001	0.0028484	-0.0157	-0.0043	0.0001	0.0060276
100	4.9939	5.0109	5.0199	0.012223	4.993	5.0037	5.0339	0.01666	-0.0261	-0.0072	0.0179	0.016782

Device Test: 105.8 HMUX Output High Leakage Current VIN_10V


TID vs Result Stats

Test Results (Lower Limit = -1.0, Upper Limit = 1.0 (uA))

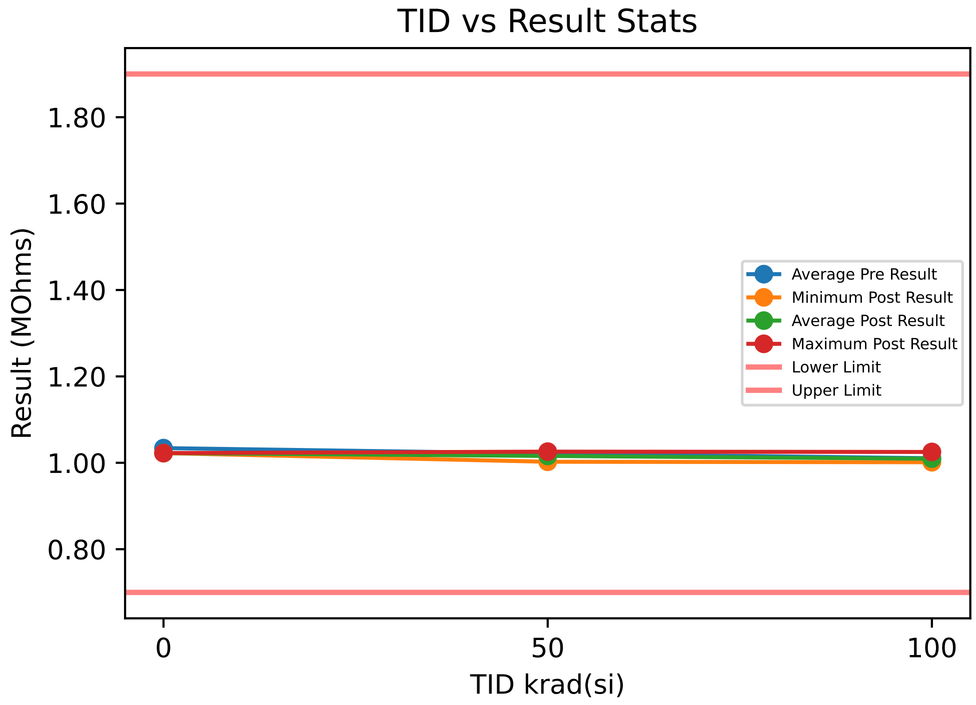
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0017	0.0026	0.0009
60	50	Biased	0.0015	0.002	0.0005
61	50	Biased	0.0015	0.0026	0.0011
63	100	Biased	0.0017	0.003	0.0013
64	100	Biased	0.0016	0.003	0.0014
65	100	Biased	0.0016	0.0024	0.0008
66	50	Unbiased	0.0016	0.002	0.0004
67	50	Unbiased	0.0017	0.0028	0.0011
68	50	Unbiased	0.0016	0.002	0.0004
69	100	Unbiased	0.0017	0.0031	0.0014
70	100	Unbiased	0.0018	0.0024	0.0006
71	100	Unbiased	0.0017	0.003	0.0013
72	0	Control	0.0018	0.002	0.0002

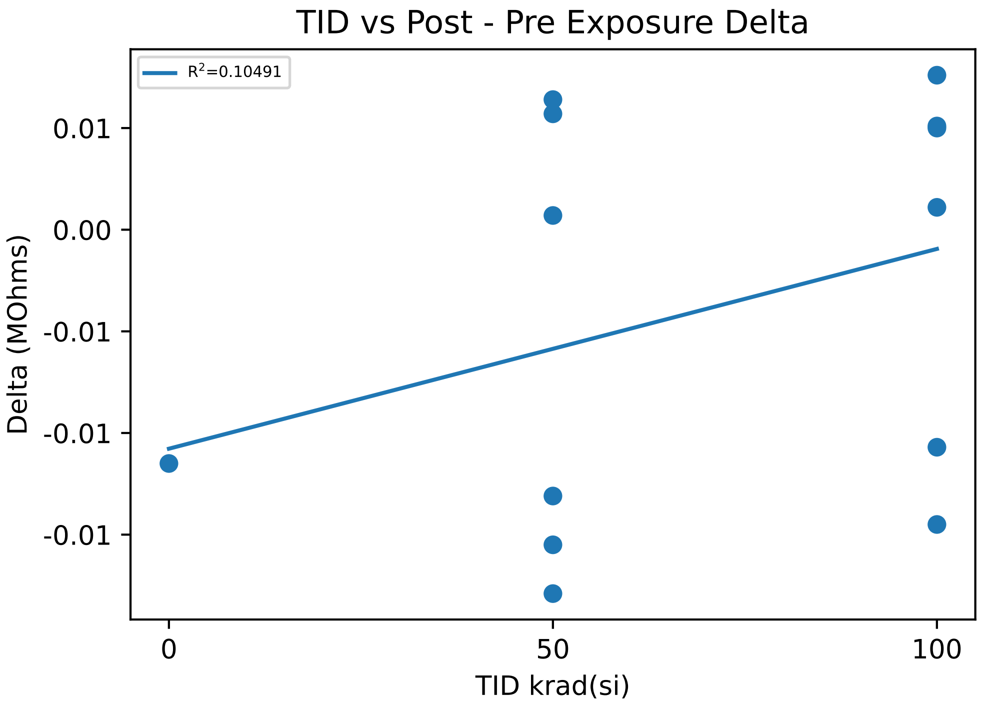

TID vs Post - Pre Exposure Delta

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0018	0.0018	0.0018		0.002	0.002	0.002		0.0002	0.0002	0.0002	
50	0.0015	0.0016	0.0017	8.9443e-05	0.002	0.0023333	0.0028	0.00037238	0.0004	0.00073333	0.0011	0.00033862
100	0.0016	0.0016833	0.0018	7.5277e-05	0.0024	0.0028167	0.0031	0.00032506	0.0006	0.0011333	0.0014	0.00034448

Device Test: 106.2 PGOOD Internal Resistance VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

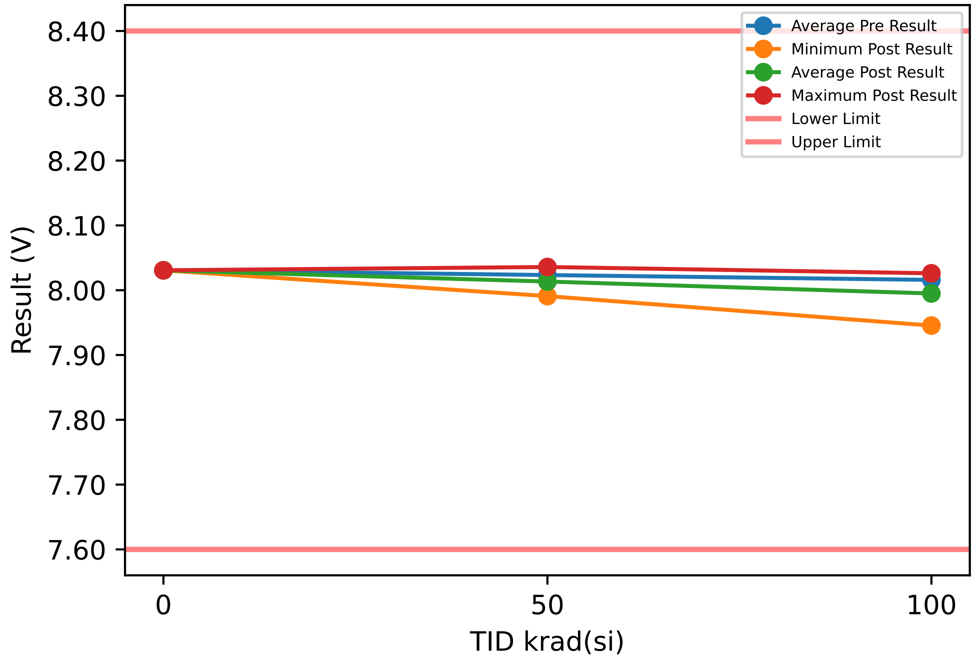
Test Results (Lower Limit = 0.7, Upper Limit = 1.9 (MOhms))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.0201	1.0258	0.0057
60	50	Biased	1.0371	1.0192	-0.0179
61	50	Biased	1.0193	1.0257	0.0064
63	100	Biased	1.0086	1.0162	0.0076
64	100	Biased	1.0358	1.0251	-0.0107
65	100	Biased	1.005	1.0061	0.0011
66	50	Unbiased	1.0179	1.0024	-0.0155
67	50	Unbiased	1.0117	1.0124	0.0007
68	50	Unbiased	1.0226	1.0095	-0.0131
69	100	Unbiased	1.0002	1.0052	0.005
70	100	Unbiased	1.0158	1.0013	-0.0145
71	100	Unbiased	0.9978	1.0029	0.0051
72	0	Control	1.034	1.0225	-0.0115

Test Statistics (MOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.034	1.034	1.034		1.0225	1.0225	1.0225		-0.0115	-0.0115	-0.0115	
50	1.0117	1.0214	1.0371	0.0084895	1.0024	1.0158	1.0258	0.0093848	-0.0179	-0.0056167	0.0064	0.011108
100	0.9978	1.0105	1.0358	0.013924	1.0013	1.0095	1.0251	0.0092638	-0.0145	-0.0010667	0.0076	0.0092509

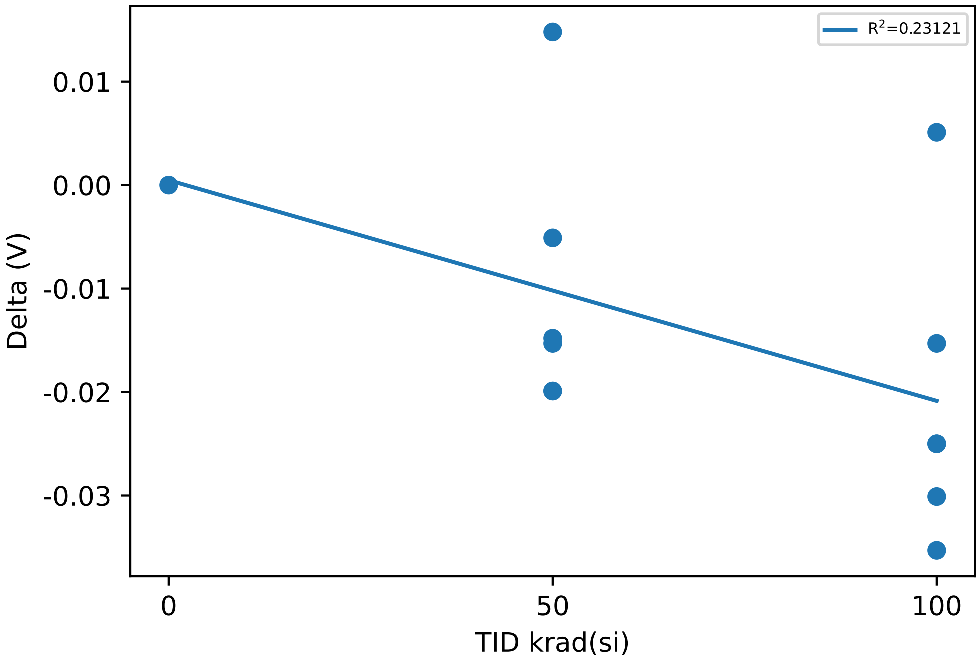
Device Test: 106.3 PGOOD Test Mode Entry V VIN_12V



TID vs Result Stats

Test Results (Lower Limit = 7.6, Upper Limit = 8.4 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	8.0307	8.0159	-0.0148
60	50	Biased	8.021	8.0358	0.0148
61	50	Biased	8.046	8.0307	-0.0153
63	100	Biased	8.021	7.9909	-0.0301
64	100	Biased	8.0261	8.0108	-0.0153
65	100	Biased	8.0108	7.9858	-0.025
66	50	Unbiased	8.0108	7.9909	-0.0199
67	50	Unbiased	8.0358	8.0159	-0.0199
68	50	Unbiased	7.996	7.9909	-0.0051
69	100	Unbiased	8.021	8.0261	0.0051
70	100	Unbiased	7.9807	7.9454	-0.0353
71	100	Unbiased	8.0358	8.0108	-0.025
72	0	Control	8.0307	8.0307	0

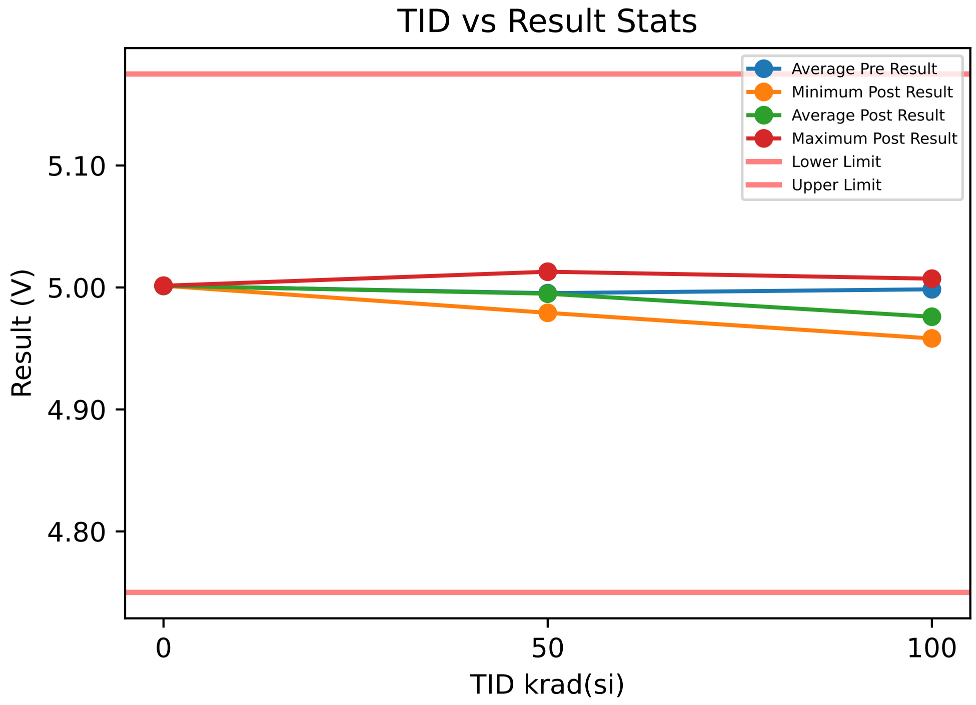


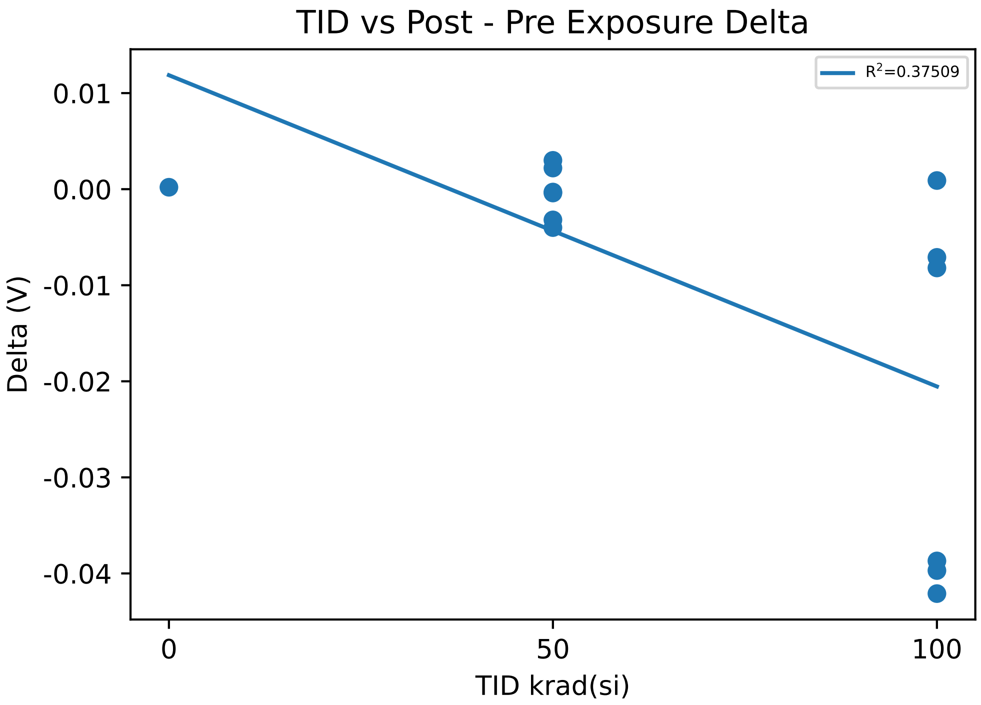
TID vs Post - Pre Exposure Delta

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0307	8.0307	8.0307		8.0307	8.0307	8.0307		0	0	0	
50	7.996	8.0234	8.046	0.018073	7.9909	8.0134	8.0358	0.01911	-0.0199	-0.010033	0.0148	0.013313
100	7.9807	8.0159	8.0358	0.019064	7.9454	7.995	8.0261	0.028383	-0.0353	-0.020933	0.0051	0.014373

Device Test: 106.4 LMUX Output High Voltage Level VIN_12V





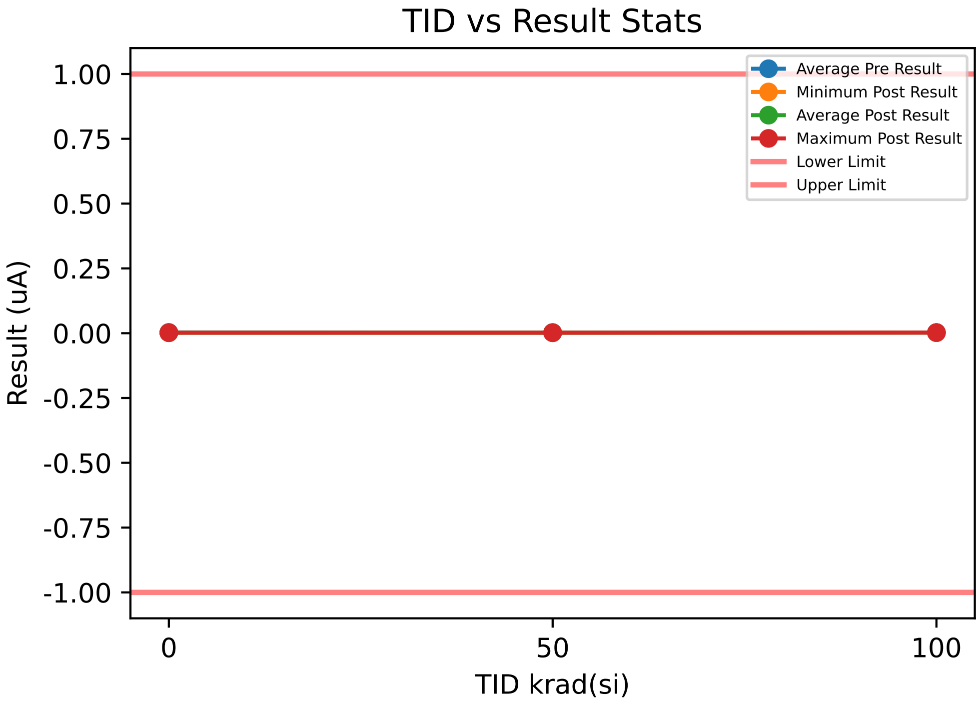
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

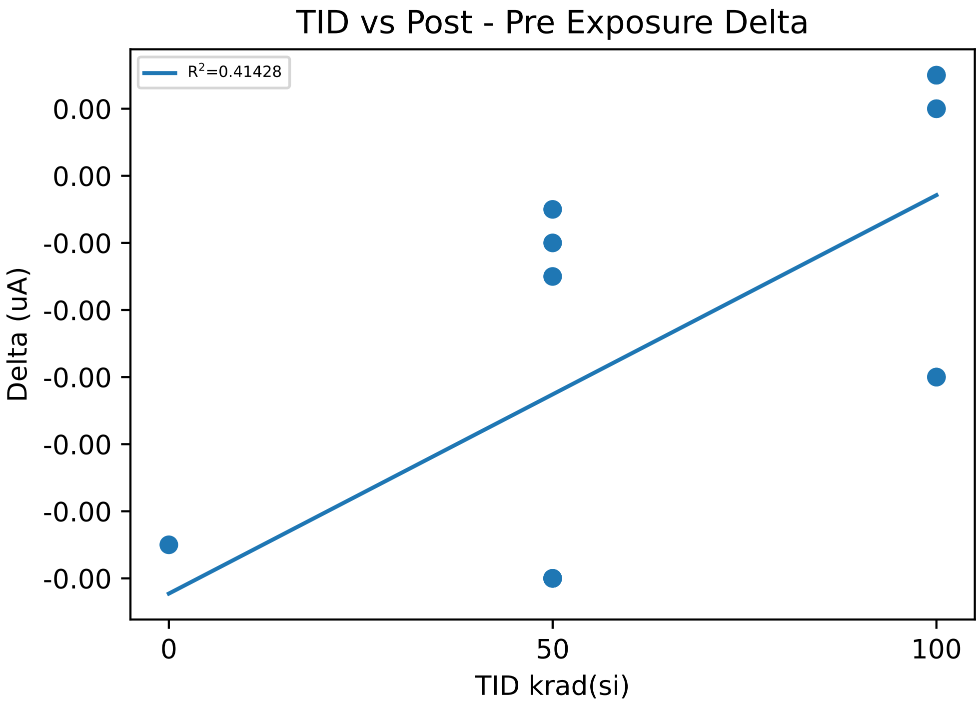
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0001	4.9997	-0.0004
60	50	Biased	4.981	4.984	0.003
61	50	Biased	5.0052	5.0074	0.0022
63	100	Biased	4.9998	4.9611	-0.0387
64	100	Biased	4.9875	4.9793	-0.0082
65	100	Biased	4.9979	4.9582	-0.0397
66	50	Unbiased	4.9824	4.9792	-0.0032
67	50	Unbiased	4.9864	4.9861	-0.0003
68	50	Unbiased	5.0169	5.0129	-0.004
69	100	Unbiased	5.0143	5.0072	-0.0071
70	100	Unbiased	4.9896	4.9905	0.0009
71	100	Unbiased	5.0018	4.9597	-0.0421
72	0	Control	5.0012	5.0014	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0012	5.0012	5.0012		5.0014	5.0014	5.0014		0.0002	0.0002	0.0002	
50	4.981	4.9953	5.0169	0.014406	4.9792	4.9949	5.0129	0.013755	-0.004	-0.00045	0.003	0.002797
100	4.9875	4.9985	5.0143	0.0096207	4.9582	4.976	5.0072	0.019996	-0.0421	-0.022483	0.0009	0.019655

Device Test: 106.5 LMUX Output High Leakage Current VIN_12V





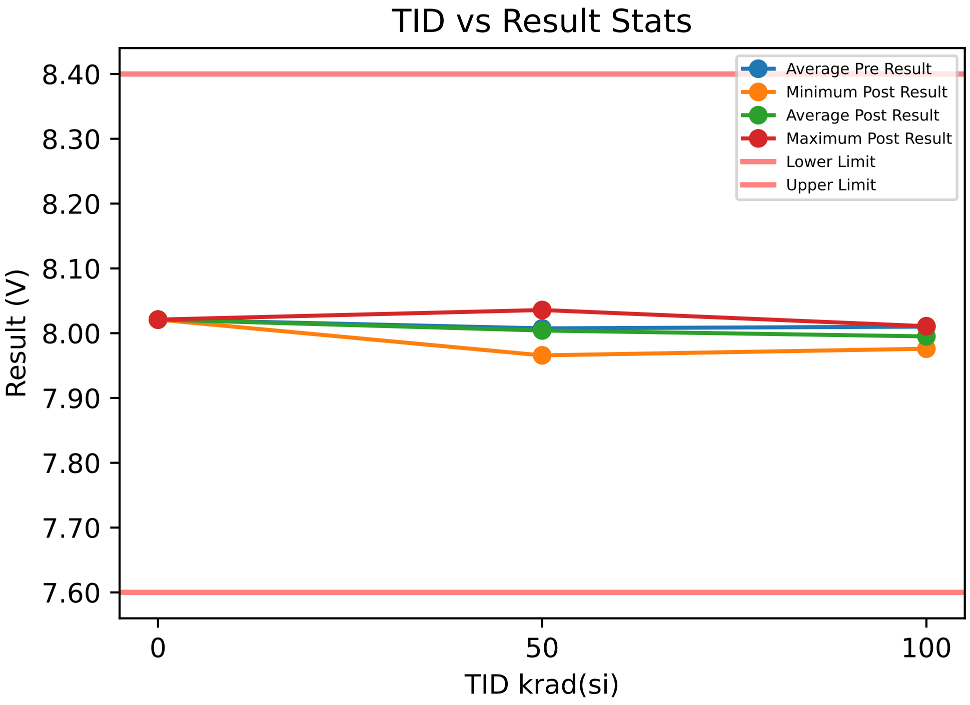
Test Results (Lower Limit = -1.0, Upper Limit = 1.0 (uA))

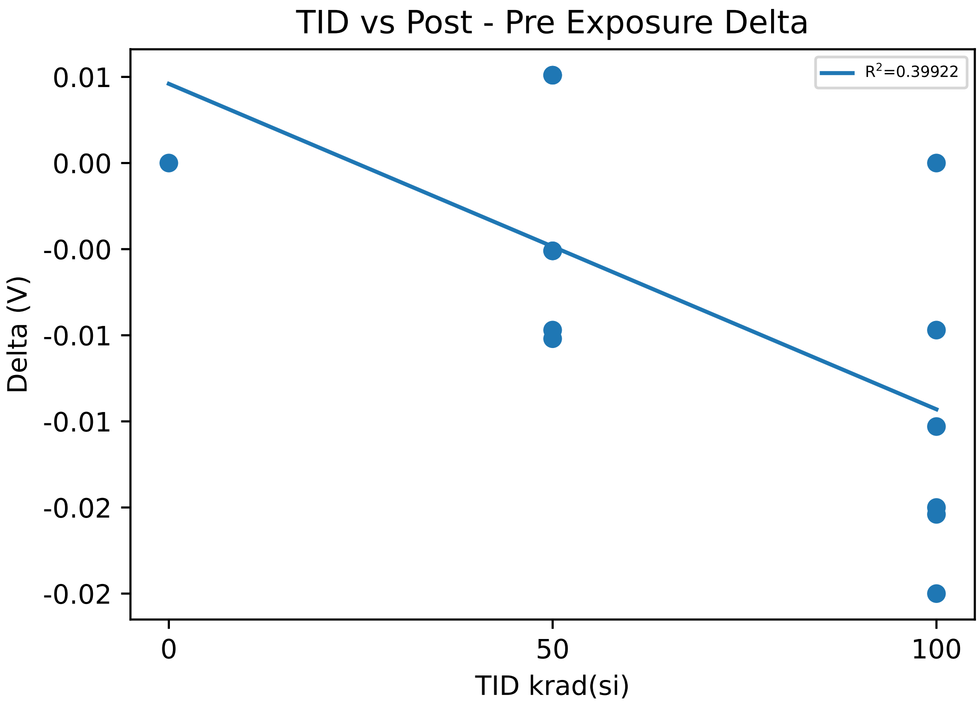
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.002	0.0019	-0.0001
60	50	Biased	0.003	0.0018	-0.0012
61	50	Biased	0.0021	0.0019	-0.0002
63	100	Biased	0.002	0.0023	0.0003
64	100	Biased	0.0028	0.0022	-0.0006
65	100	Biased	0.002	0.0023	0.0003
66	50	Unbiased	0.0031	0.0019	-0.0012
67	50	Unbiased	0.0022	0.0019	-0.0003
68	50	Unbiased	0.003	0.0018	-0.0012
69	100	Unbiased	0.0021	0.0023	0.0002
70	100	Unbiased	0.003	0.0024	-0.0006
71	100	Unbiased	0.0021	0.0023	0.0002
72	0	Control	0.003	0.0019	-0.0011

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.003	0.003	0.003		0.0019	0.0019	0.0019		-0.0011	-0.0011	-0.0011	
50	0.002	0.0025667	0.0031	0.0005164	0.0018	0.0018667	0.0019	5.164e-05	-0.0012	-0.0007	-0.0001	0.00055136
100	0.002	0.0023333	0.003	0.00044572	0.0022	0.0023	0.0024	6.3246e-05	-0.0006	-3.3333e-05	0.0003	0.00044121

Device Test: 106.6 HEN_TST Test Mode Entry V VIN_12V





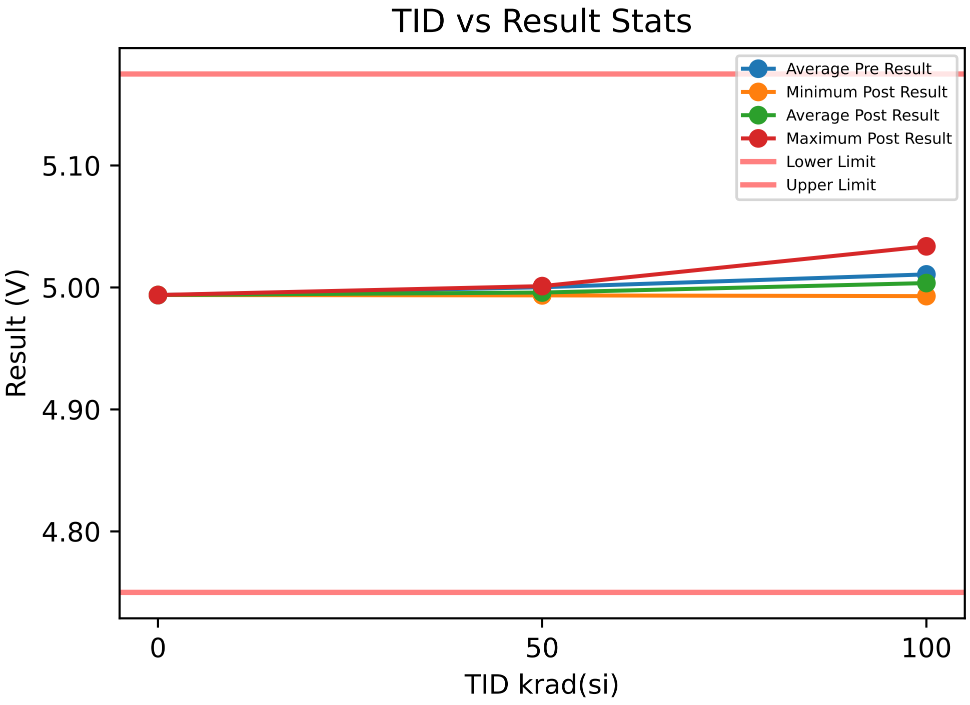
Test Results (Lower Limit = 7.6, Upper Limit = 8.4 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	8.0057	7.996	-0.0097
60	50	Biased	8.0057	8.0108	0.0051
61	50	Biased	8.0159	8.0108	-0.0051
63	100	Biased	8.0108	8.0108	0
64	100	Biased	7.996	7.9807	-0.0153
65	100	Biased	7.996	7.976	-0.02
66	50	Unbiased	8.0159	8.0057	-0.0102
67	50	Unbiased	7.9607	7.9658	0.0051
68	50	Unbiased	8.0409	8.0358	-0.0051
69	100	Unbiased	8.021	7.996	-0.025
70	100	Unbiased	8.0261	8.0057	-0.0204
71	100	Unbiased	8.0108	8.0011	-0.0097
72	0	Control	8.021	8.021	0

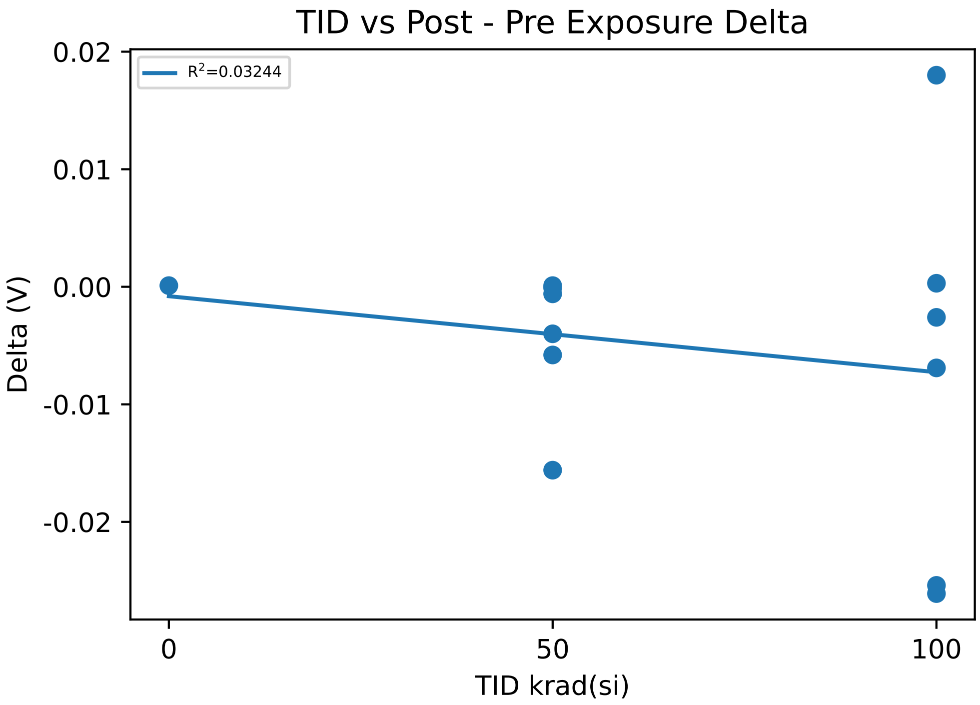
Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.021	8.021	8.021		8.021	8.021	8.021		0	0	0	
50	7.9607	8.0075	8.0409	0.026281	7.9658	8.0042	8.0358	0.022933	-0.0102	-0.0033167	0.0051	0.0068727
100	7.996	8.0101	8.0261	0.012437	7.976	7.995	8.0108	0.013913	-0.025	-0.015067	0	0.0090257

Device Test: 106.7 HMUX Output High Voltage Level VIN_12V



TID vs Result Stats



TID vs Post - Pre Exposure Delta

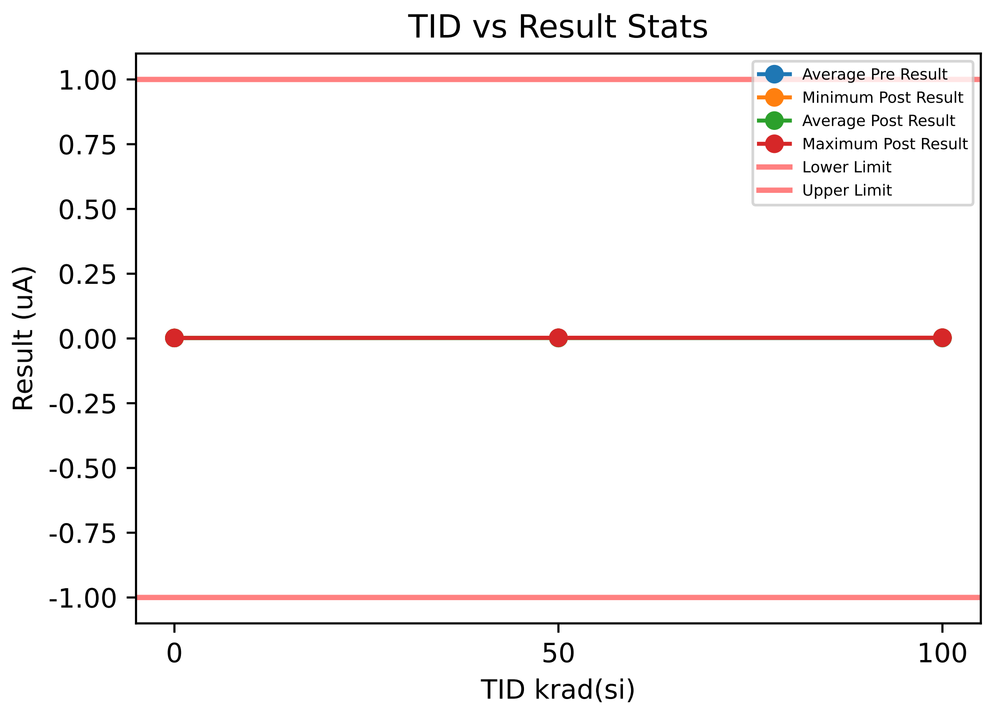
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

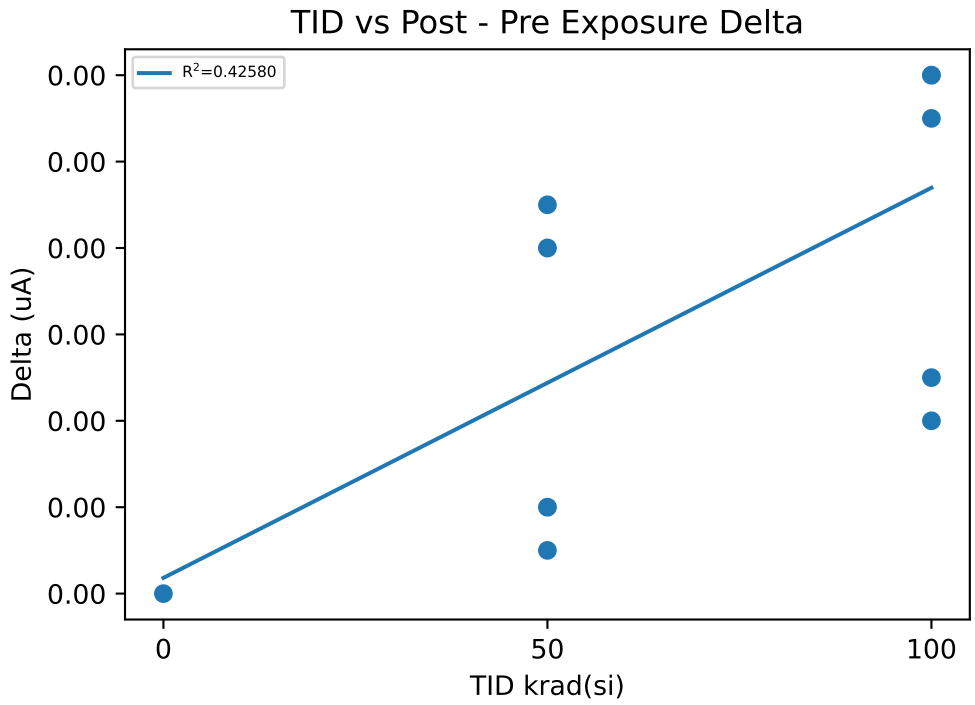
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0014	4.9956	-0.0058
60	50	Biased	4.9941	4.9935	-0.0006
61	50	Biased	5.0007	4.9967	-0.004
63	100	Biased	4.9965	4.9939	-0.0026
64	100	Biased	5.0195	4.9941	-0.0254
65	100	Biased	5.0196	5.0127	-0.0069
66	50	Unbiased	4.9943	4.9944	0.0001
67	50	Unbiased	4.9938	4.9937	-0.0001
68	50	Unbiased	5.0167	5.0011	-0.0156
69	100	Unbiased	5.019	4.9929	-0.0261
70	100	Unbiased	4.994	4.9943	0.0003
71	100	Unbiased	5.0157	5.0337	0.018
72	0	Control	4.9937	4.9938	0.0001

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9937	4.9937	4.9937		4.9938	4.9938	4.9938		0.0001	0.0001	0.0001	
50	4.9938	5.0002	5.0167	0.0087967	4.9935	4.9958	5.0011	0.0028493	-0.0156	-0.0043333	0.0001	0.0060119
100	4.994	5.0107	5.0196	0.012092	4.9929	5.0036	5.0337	0.016578	-0.0261	-0.0071167	0.018	0.016739

Device Test: 106.8 HMUX Output High Leakage Current VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

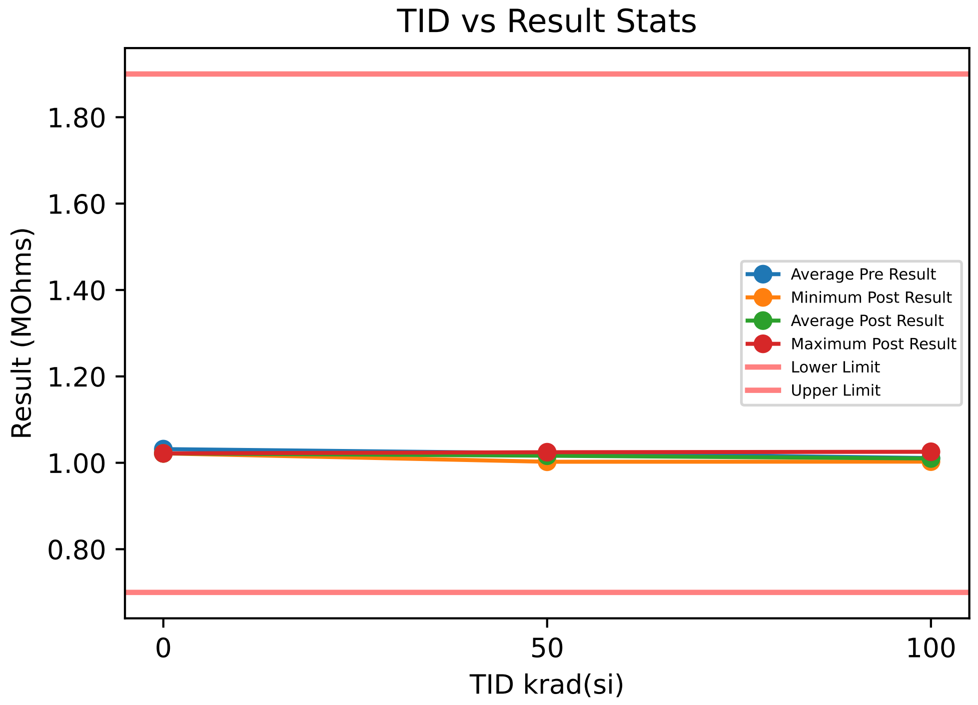
Test Results (Lower Limit = -1.0, Upper Limit = 1.0 (uA))

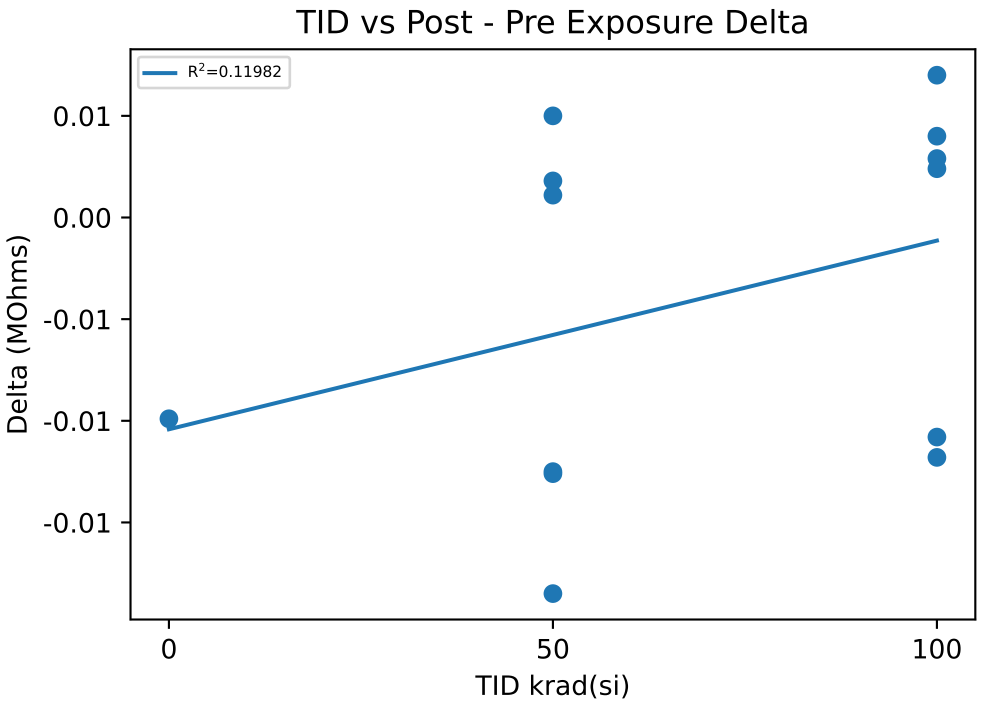
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0016	0.0026	0.001
60	50	Biased	0.0016	0.0019	0.0003
61	50	Biased	0.0016	0.0026	0.001
63	100	Biased	0.0016	0.003	0.0014
64	100	Biased	0.0016	0.003	0.0014
65	100	Biased	0.0016	0.0022	0.0006
66	50	Unbiased	0.0017	0.0021	0.0004
67	50	Unbiased	0.0017	0.0028	0.0011
68	50	Unbiased	0.0016	0.002	0.0004
69	100	Unbiased	0.0017	0.003	0.0013
70	100	Unbiased	0.0016	0.0023	0.0007
71	100	Unbiased	0.0016	0.003	0.0014
72	0	Control	0.0018	0.002	0.0002

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0018	0.0018	0.0018		0.002	0.002	0.002		0.0002	0.0002	0.0002	
50	0.0016	0.0016333	0.0017	5.164e-05	0.0019	0.0023333	0.0028	0.00037771	0.0003	0.0007	0.0011	0.00036878
100	0.0016	0.0016167	0.0017	4.0825e-05	0.0022	0.00275	0.003	0.00038859	0.0006	0.0011333	0.0014	0.00037771

Device Test: 107.2 PGOOD Internal Resistance VIN_14V





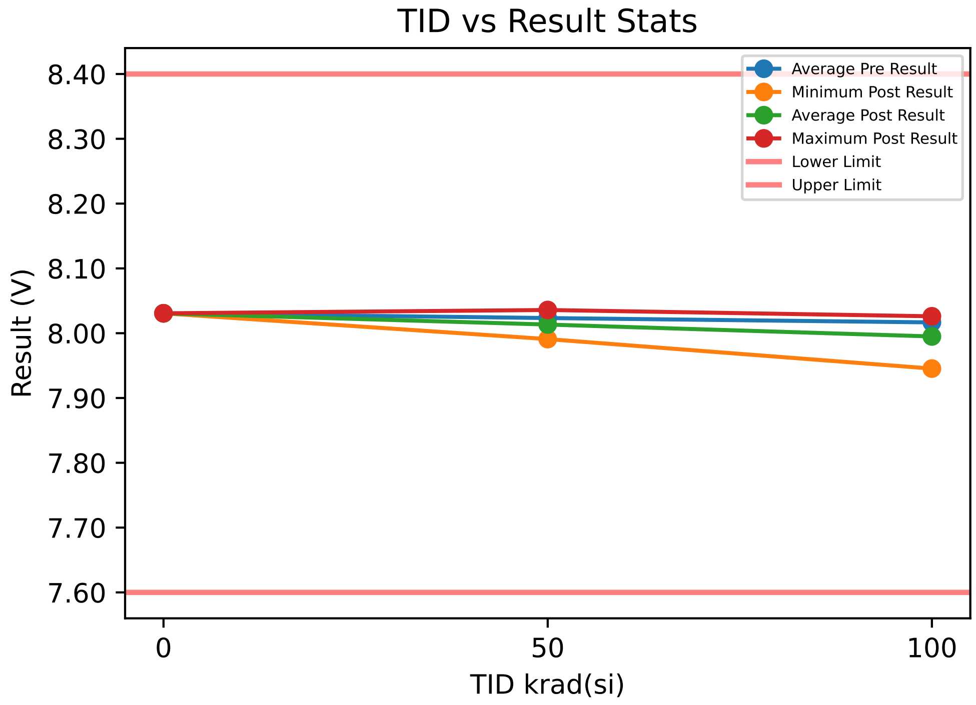
Test Results (Lower Limit = 0.7, Upper Limit = 1.9 (MOhms))

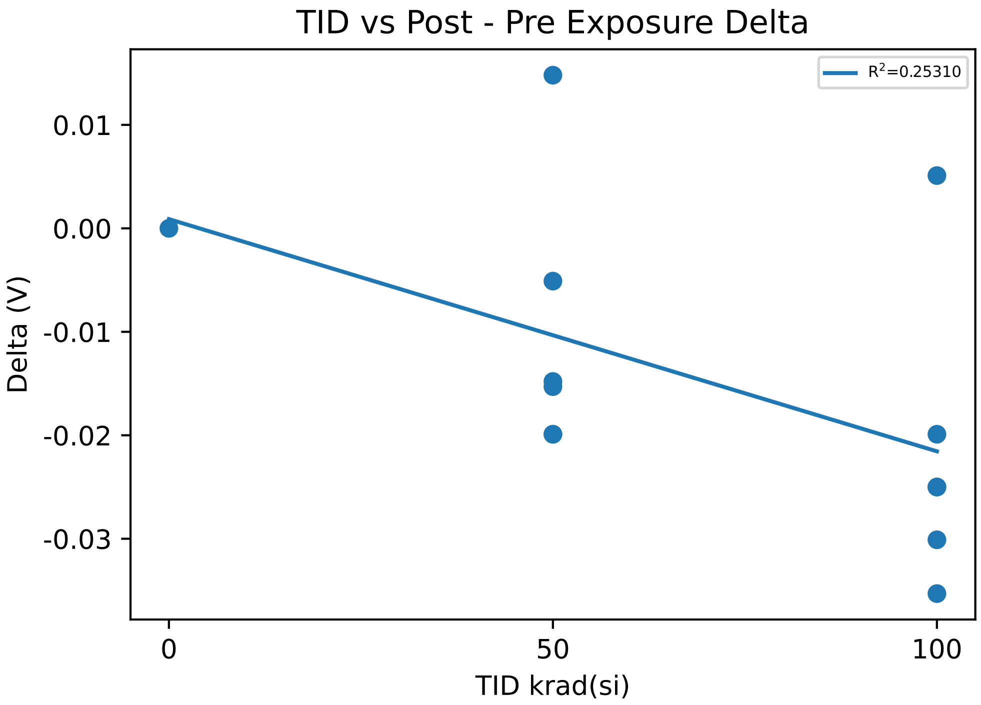
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.0229	1.024	0.0011
60	50	Biased	1.037	1.0245	-0.0125
61	50	Biased	1.0194	1.0244	0.005
63	100	Biased	1.0095	1.0165	0.007
64	100	Biased	1.0363	1.0255	-0.0108
65	100	Biased	1.0057	1.0086	0.0029
66	50	Unbiased	1.0209	1.0024	-0.0185
67	50	Unbiased	1.0121	1.0139	0.0018
68	50	Unbiased	1.0216	1.009	-0.0126
69	100	Unbiased	0.9993	1.0033	0.004
70	100	Unbiased	1.0145	1.0027	-0.0118
71	100	Unbiased	1.0006	1.003	0.0024
72	0	Control	1.0317	1.0218	-0.0099

Test Statistics (MOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0317	1.0317	1.0317		1.0218	1.0218	1.0218		-0.0099	-0.0099	-0.0099	
50	1.0121	1.0223	1.037	0.0081406	1.0024	1.0164	1.0245	0.0094273	-0.0185	-0.00595	0.005	0.0097396
100	0.9993	1.011	1.0363	0.013622	1.0027	1.0099	1.0255	0.009291	-0.0118	-0.00105	0.007	0.0081048

Device Test: 107.3 PGOOD Test Mode Entry V VIN_14V





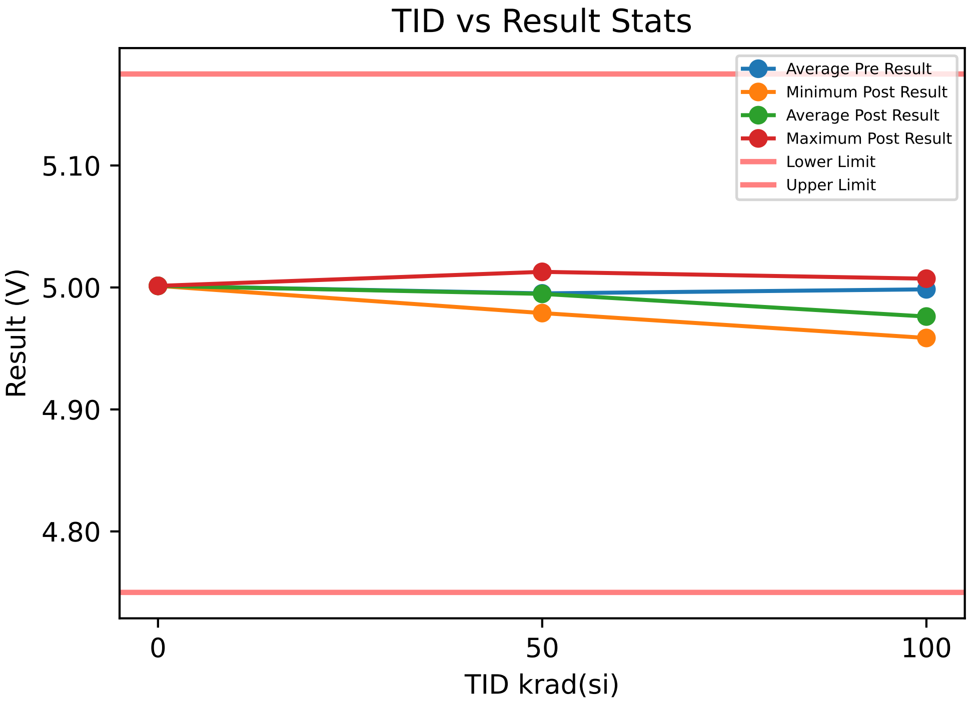
Test Results (Lower Limit = 7.6, Upper Limit = 8.4 (V))

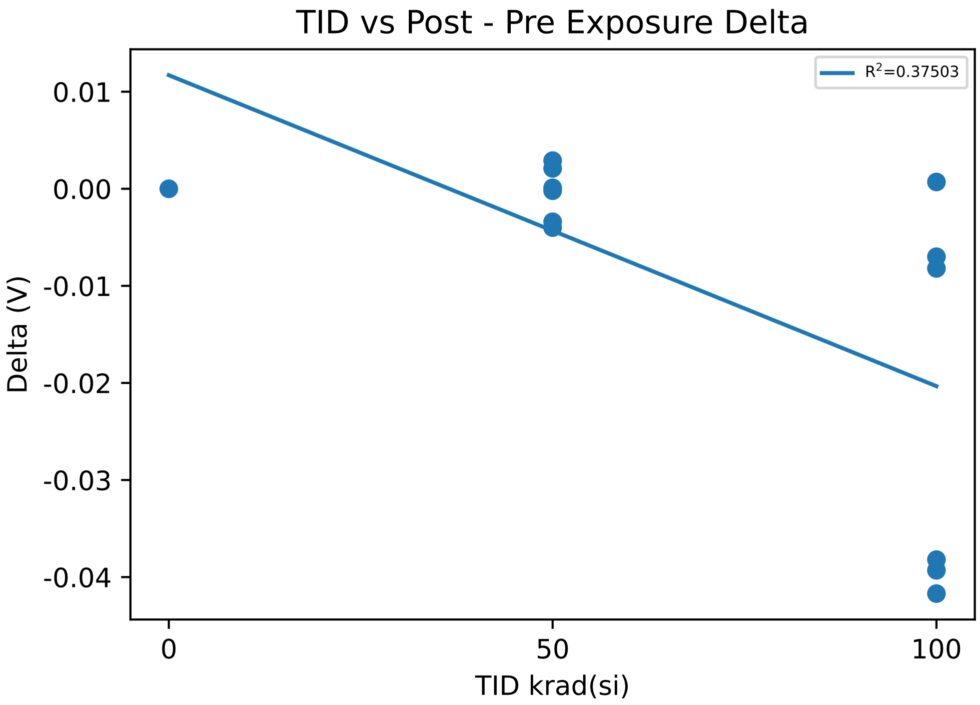
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	8.0307	8.0159	-0.0148
60	50	Biased	8.021	8.0358	0.0148
61	50	Biased	8.046	8.0307	-0.0153
63	100	Biased	8.021	7.9909	-0.0301
64	100	Biased	8.0307	8.0108	-0.0199
65	100	Biased	8.0108	7.9858	-0.025
66	50	Unbiased	8.0108	7.9909	-0.0199
67	50	Unbiased	8.0358	8.0159	-0.0199
68	50	Unbiased	7.996	7.9909	-0.0051
69	100	Unbiased	8.021	8.0261	0.0051
70	100	Unbiased	7.9807	7.9454	-0.0353
71	100	Unbiased	8.0358	8.0108	-0.025
72	0	Control	8.0307	8.0307	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0307	8.0307	8.0307		8.0307	8.0307	8.0307		0	0	0	
50	7.996	8.0234	8.046	0.018073	7.9909	8.0134	8.0358	0.01911	-0.0199	-0.010033	0.0148	0.013313
100	7.9807	8.0167	8.0358	0.01964	7.9454	7.995	8.0261	0.028383	-0.0353	-0.0217	0.0051	0.014134

Device Test: 107.4 LMUX Output High Voltage Level VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

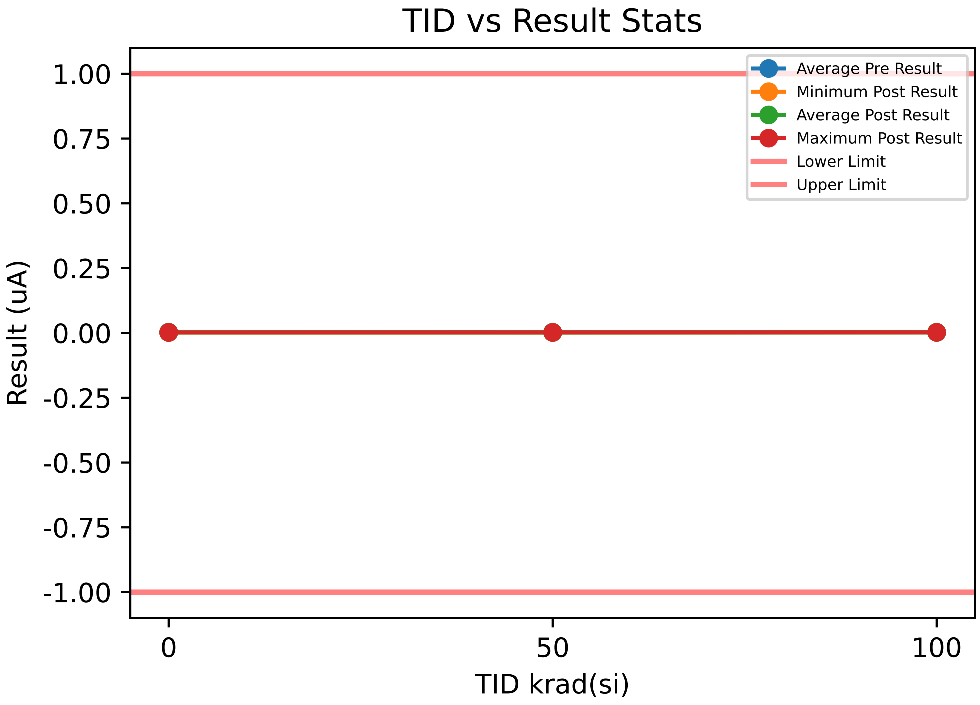
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

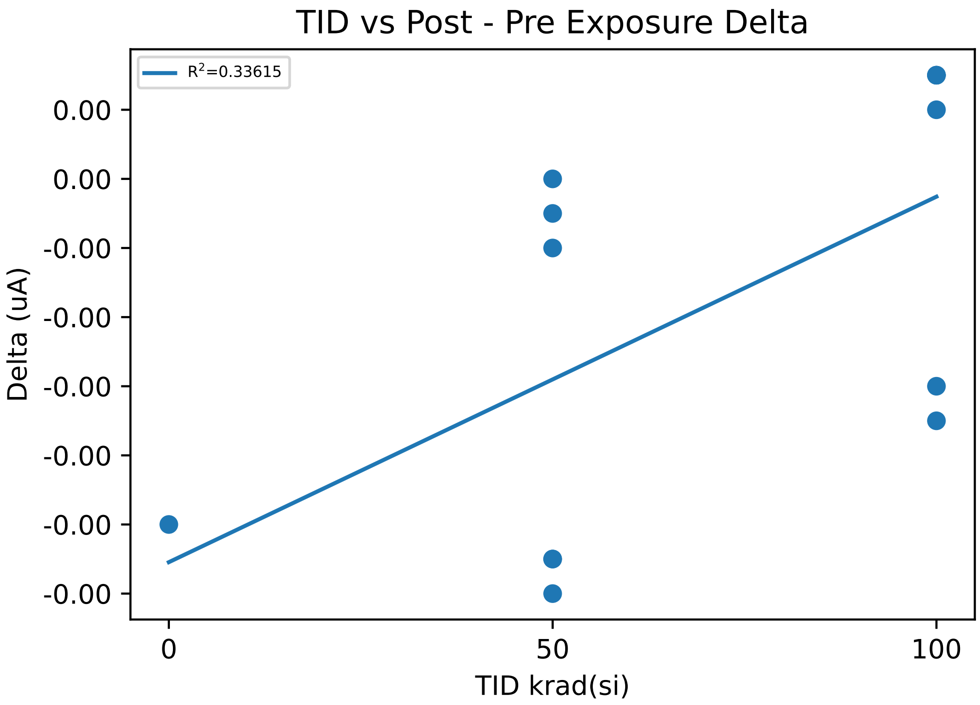
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.9998	4.9996	-0.0002
60	50	Biased	4.9809	4.9838	0.0029
61	50	Biased	5.0049	5.007	0.0021
63	100	Biased	4.9998	4.9616	-0.0382
64	100	Biased	4.9875	4.9793	-0.0082
65	100	Biased	4.9979	4.9586	-0.0393
66	50	Unbiased	4.9824	4.979	-0.0034
67	50	Unbiased	4.9861	4.9862	0.0001
68	50	Unbiased	5.0168	5.0128	-0.004
69	100	Unbiased	5.0142	5.0072	-0.007
70	100	Unbiased	4.9896	4.9903	0.0007
71	100	Unbiased	5.0017	4.96	-0.0417
72	0	Control	5.0013	5.0013	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0013	5.0013	5.0013		5.0013	5.0013	5.0013		0	0	0	
50	4.9809	4.9951	5.0168	0.014373	4.979	4.9947	5.0128	0.013715	-0.004	-0.00041667	0.0029	0.0028067
100	4.9875	4.9984	5.0142	0.009581	4.9586	4.9762	5.0072	0.019773	-0.0417	-0.022283	0.0007	0.019391

Device Test: 107.5 LMUX Output High Leakage Current VIN_14V





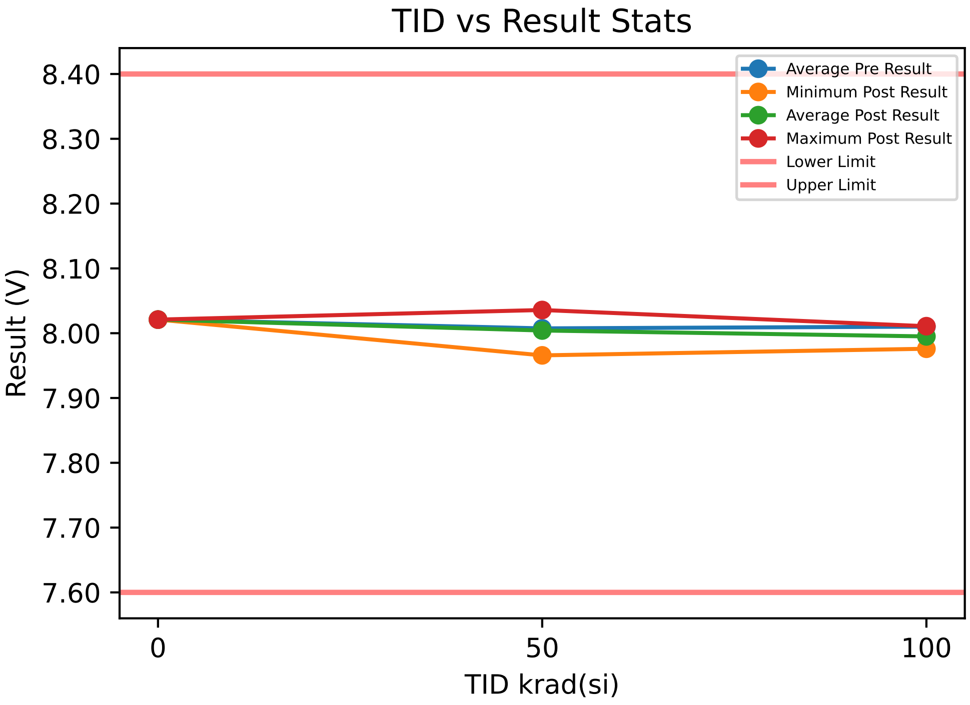
Test Results (Lower Limit = -1.0, Upper Limit = 1.0 (uA))

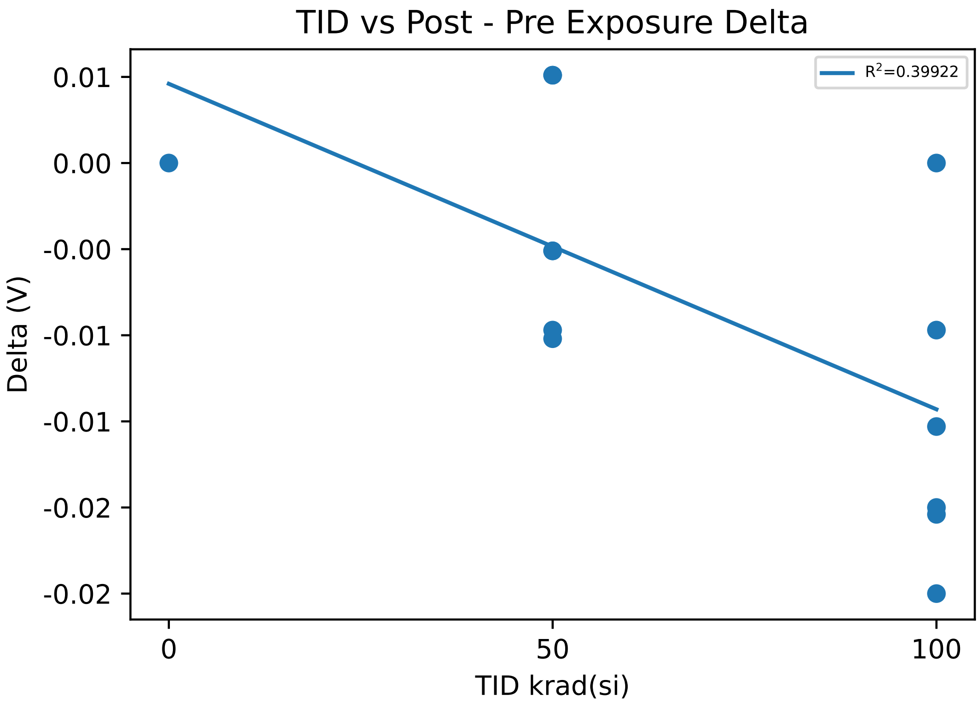
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.002	0.0019	-0.0001
60	50	Biased	0.003	0.0018	-0.0012
61	50	Biased	0.0022	0.002	-0.0002
63	100	Biased	0.002	0.0023	0.0003
64	100	Biased	0.0028	0.0022	-0.0006
65	100	Biased	0.002	0.0023	0.0003
66	50	Unbiased	0.0031	0.002	-0.0011
67	50	Unbiased	0.0021	0.0021	0
68	50	Unbiased	0.003	0.0019	-0.0011
69	100	Unbiased	0.0021	0.0023	0.0002
70	100	Unbiased	0.003	0.0023	-0.0007
71	100	Unbiased	0.002	0.0023	0.0003
72	0	Control	0.003	0.002	-0.001

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.003	0.003	0.003		0.002	0.002	0.002		-0.001	-0.001	-0.001	
50	0.002	0.0025667	0.0031	0.0005164	0.0018	0.00195	0.0021	0.00010488	-0.0012	-0.00061667	0	0.00057067
100	0.002	0.0023167	0.003	0.00045789	0.0022	0.0022833	0.0023	4.0825e-05	-0.0007	-3.3333e-05	0.0003	0.00048028

Device Test: 107.6 HEN_TST Test Mode Entry V VIN_14V





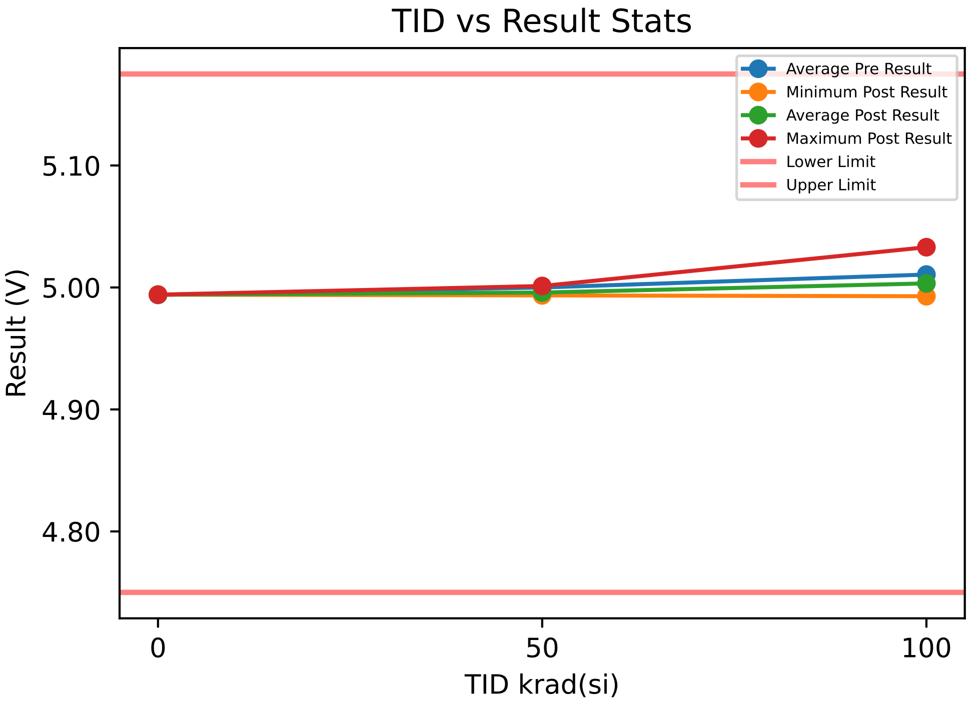
Test Results (Lower Limit = 7.6, Upper Limit = 8.4 (V))

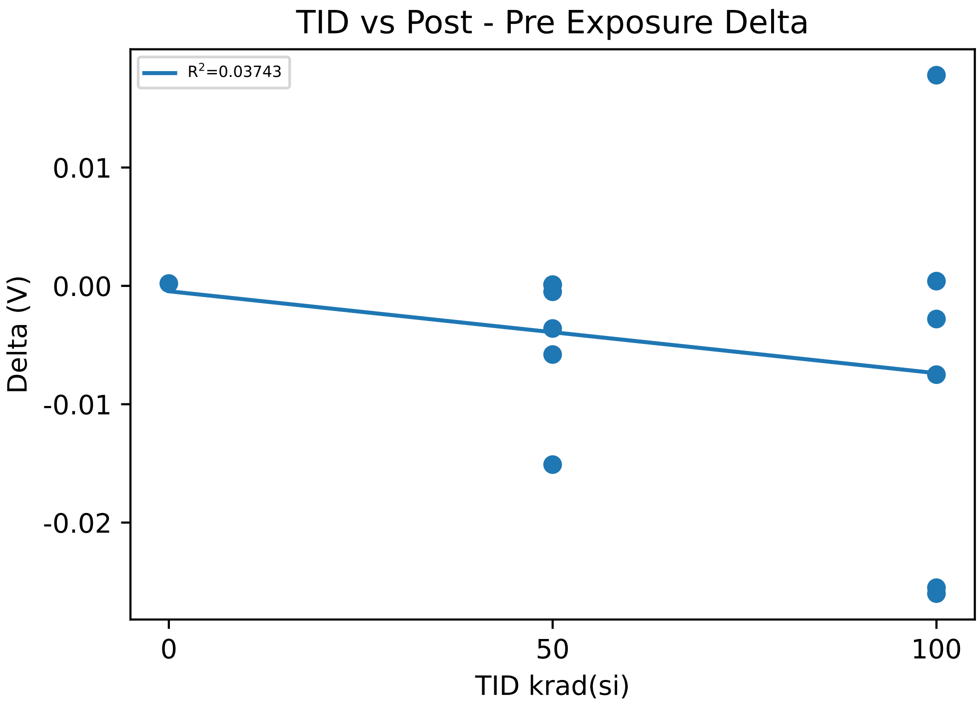
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	8.0057	7.996	-0.0097
60	50	Biased	8.0057	8.0108	0.0051
61	50	Biased	8.0159	8.0108	-0.0051
63	100	Biased	8.0108	8.0108	0
64	100	Biased	7.996	7.9807	-0.0153
65	100	Biased	7.996	7.976	-0.02
66	50	Unbiased	8.0159	8.0057	-0.0102
67	50	Unbiased	7.9607	7.9658	0.0051
68	50	Unbiased	8.0409	8.0358	-0.0051
69	100	Unbiased	8.021	7.996	-0.025
70	100	Unbiased	8.0261	8.0057	-0.0204
71	100	Unbiased	8.0108	8.0011	-0.0097
72	0	Control	8.021	8.021	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.021	8.021	8.021		8.021	8.021	8.021		0	0	0	
50	7.9607	8.0075	8.0409	0.026281	7.9658	8.0042	8.0358	0.022933	-0.0102	-0.0033167	0.0051	0.0068727
100	7.996	8.0101	8.0261	0.012437	7.976	7.995	8.0108	0.013913	-0.025	-0.015067	0	0.0090257

Device Test: 107.7 HMUX Output High Voltage Level VIN_14V





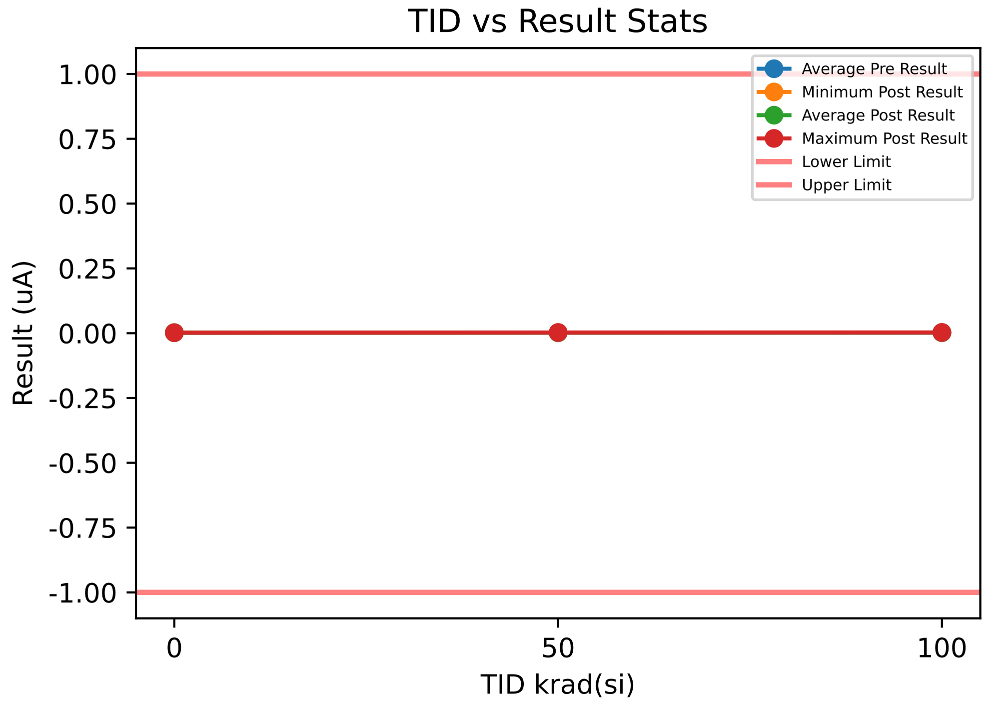
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

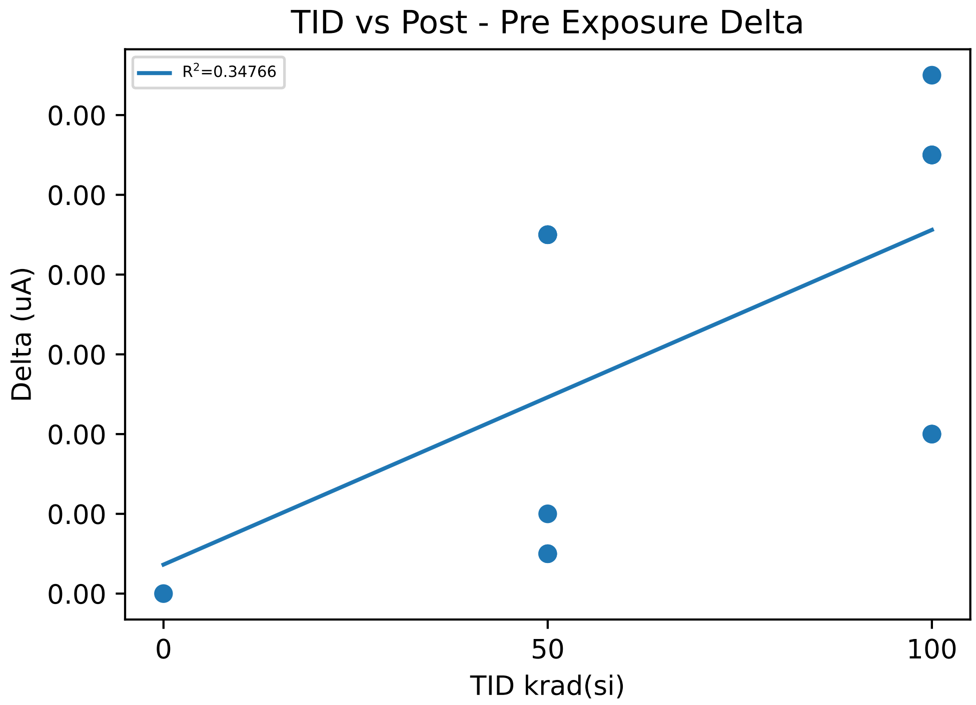
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0011	4.9953	-0.0058
60	50	Biased	4.994	4.9935	-0.0005
61	50	Biased	5.0003	4.9967	-0.0036
63	100	Biased	4.9965	4.9937	-0.0028
64	100	Biased	5.0193	4.9938	-0.0255
65	100	Biased	5.0196	5.0121	-0.0075
66	50	Unbiased	4.9944	4.9945	0.0001
67	50	Unbiased	4.9937	4.9938	0.0001
68	50	Unbiased	5.0163	5.0012	-0.0151
69	100	Unbiased	5.0188	4.9928	-0.026
70	100	Unbiased	4.9941	4.9945	0.0004
71	100	Unbiased	5.0152	5.033	0.0178
72	0	Control	4.9939	4.9941	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9939	4.9939	4.9939		4.9941	4.9941	4.9941		0.0002	0.0002	0.0002	
50	4.9937	5	5.0163	0.0086491	4.9935	4.9958	5.0012	0.0028703	-0.0151	-0.0041333	0.0001	0.0058715
100	4.9941	5.0106	5.0196	0.011968	4.9928	5.0033	5.033	0.016307	-0.026	-0.0072667	0.0178	0.016676

Device Test: 107.8 HMUX Output High Leakage Current VIN_14V





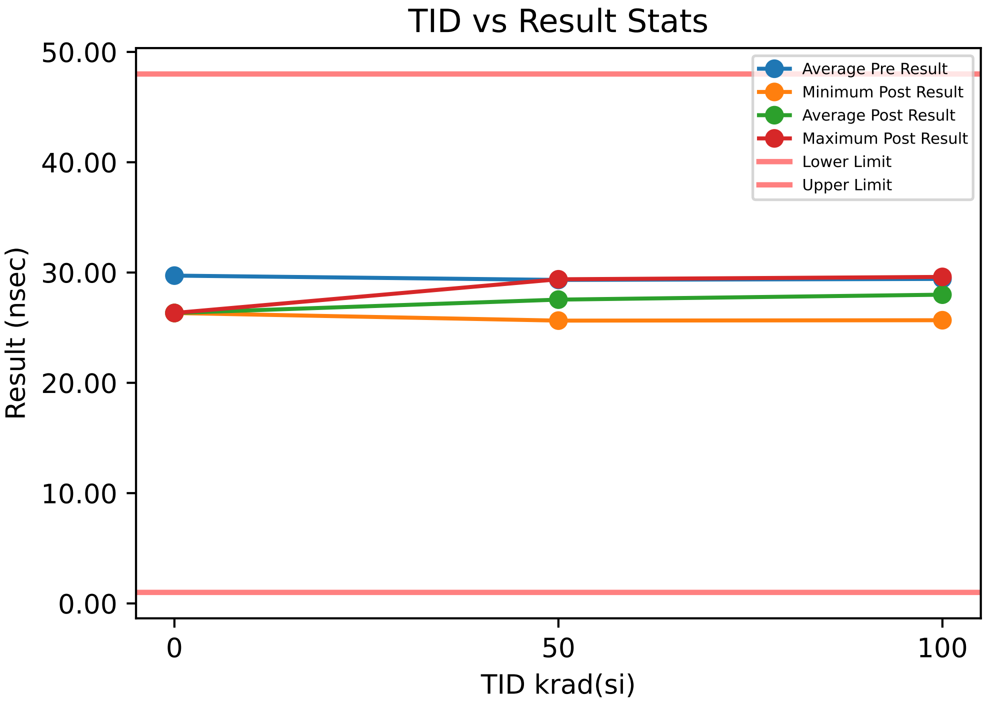
Test Results (Lower Limit = -1.0, Upper Limit = 1.0 (uA))

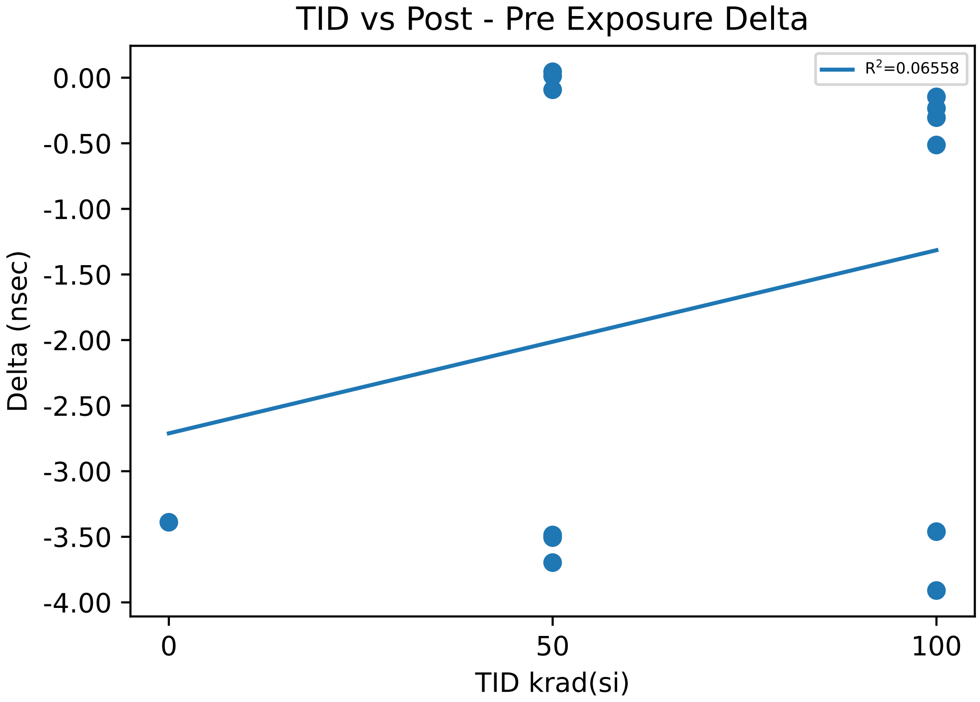
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0016	0.0027	0.0011
60	50	Biased	0.0016	0.0019	0.0003
61	50	Biased	0.0016	0.0027	0.0011
63	100	Biased	0.0015	0.003	0.0015
64	100	Biased	0.0016	0.0029	0.0013
65	100	Biased	0.0015	0.0021	0.0006
66	50	Unbiased	0.0017	0.0021	0.0004
67	50	Unbiased	0.0016	0.0027	0.0011
68	50	Unbiased	0.0017	0.002	0.0003
69	100	Unbiased	0.0017	0.003	0.0013
70	100	Unbiased	0.0017	0.0023	0.0006
71	100	Unbiased	0.0016	0.0029	0.0013
72	0	Control	0.0018	0.002	0.0002

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0018	0.0018	0.0018		0.002	0.002	0.002		0.0002	0.0002	0.0002	
50	0.0016	0.0016333	0.0017	5.164e-05	0.0019	0.00235	0.0027	0.00038859	0.0003	0.00071667	0.0011	0.00042151
100	0.0015	0.0016	0.0017	8.9443e-05	0.0021	0.0027	0.003	0.00039497	0.0006	0.0011	0.0015	0.00039497

Device Test: 110.0 Prop Delay LO Off PWM VIN_10V





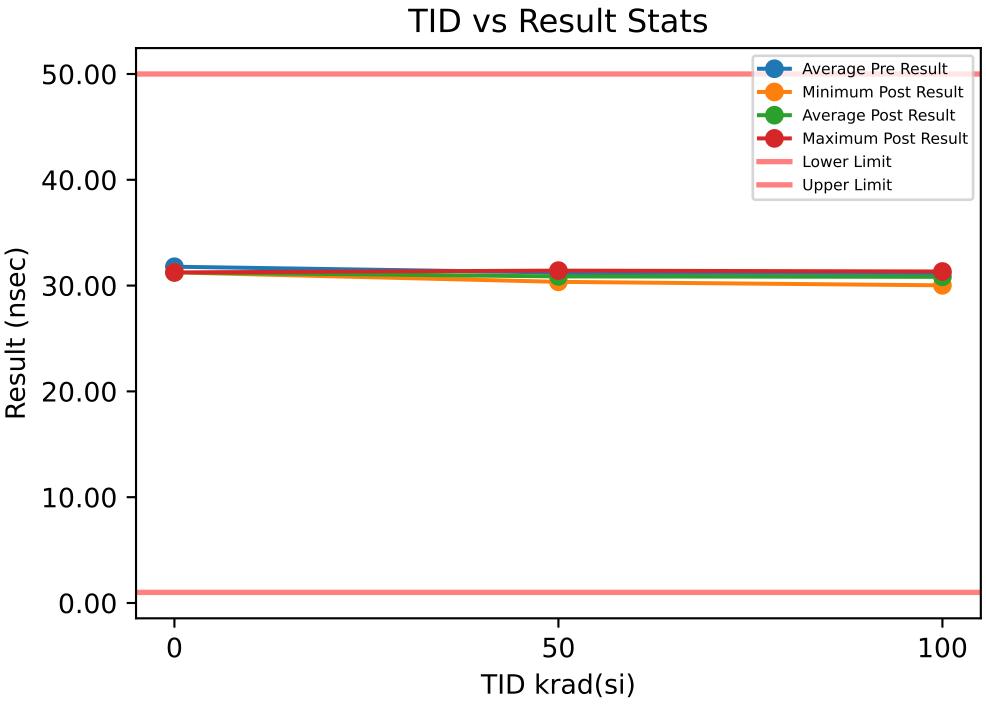
Test Results (Lower Limit = 1.0, Upper Limit = 48.0 (nsec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	29.052	29.097	0.0454
60	50	Biased	29.389	25.883	-3.506
61	50	Biased	29.155	29.167	0.0124
63	100	Biased	29.053	28.907	-0.1461
64	100	Biased	29.617	29.104	-0.5131
65	100	Biased	29.173	25.713	-3.4607
66	50	Unbiased	29.573	26.086	-3.4862
67	50	Unbiased	29.481	29.389	-0.0919
68	50	Unbiased	29.337	25.641	-3.6968
69	100	Unbiased	29.259	28.954	-0.3047
70	100	Unbiased	29.586	25.676	-3.9095
71	100	Unbiased	29.837	29.604	-0.2336
72	0	Control	29.721	26.332	-3.3891

Test Statistics (nsec)

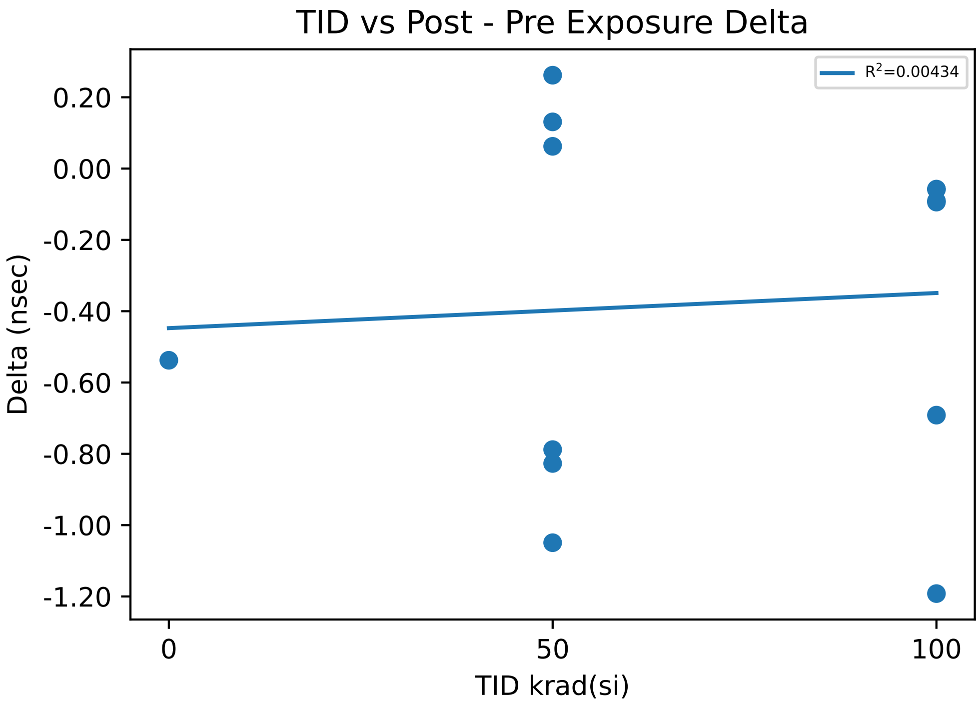
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	29.721	29.721	29.721		26.332	26.332	26.332		-3.3891	-3.3891	-3.3891	
50	29.052	29.331	29.573	0.19669	25.641	27.544	29.389	1.8415	-3.6968	-1.7872	0.0454	1.9472
100	29.053	29.421	29.837	0.30402	25.676	27.993	29.604	1.7974	-3.9095	-1.4279	-0.1461	1.7583

Device Test: 110.1 Prop Delay HO Off PWM VIN_10V



Test Results (Lower Limit = 1.0, Upper Limit = 50.0 (nsec))

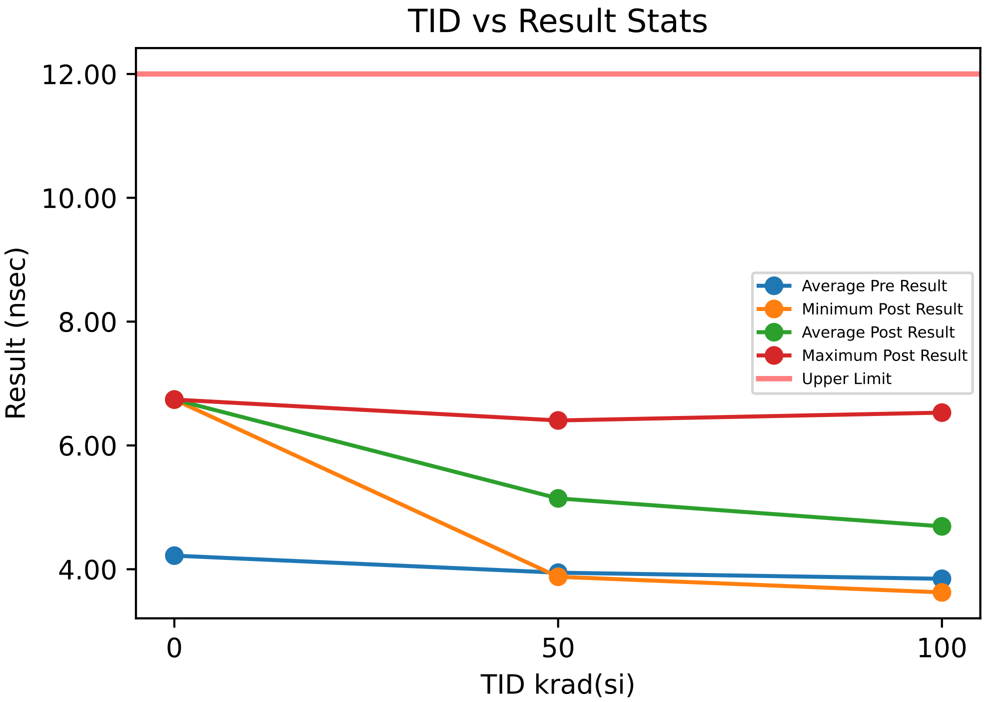
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	31.04	31.302	0.2619
60	50	Biased	31.433	30.384	-1.0493
61	50	Biased	31.271	31.334	0.0624
63	100	Biased	31.141	31.083	-0.0576
64	100	Biased	31.423	31.332	-0.0907
65	100	Biased	31.145	30.454	-0.6915
66	50	Unbiased	31.142	30.354	-0.7882
67	50	Unbiased	31.285	31.416	0.131
68	50	Unbiased	31.232	30.405	-0.827
69	100	Unbiased	30.905	30.811	-0.094
70	100	Unbiased	31.217	30.025	-1.192
71	100	Unbiased	31.318	31.26	-0.058
72	0	Control	31.784	31.247	-0.5376

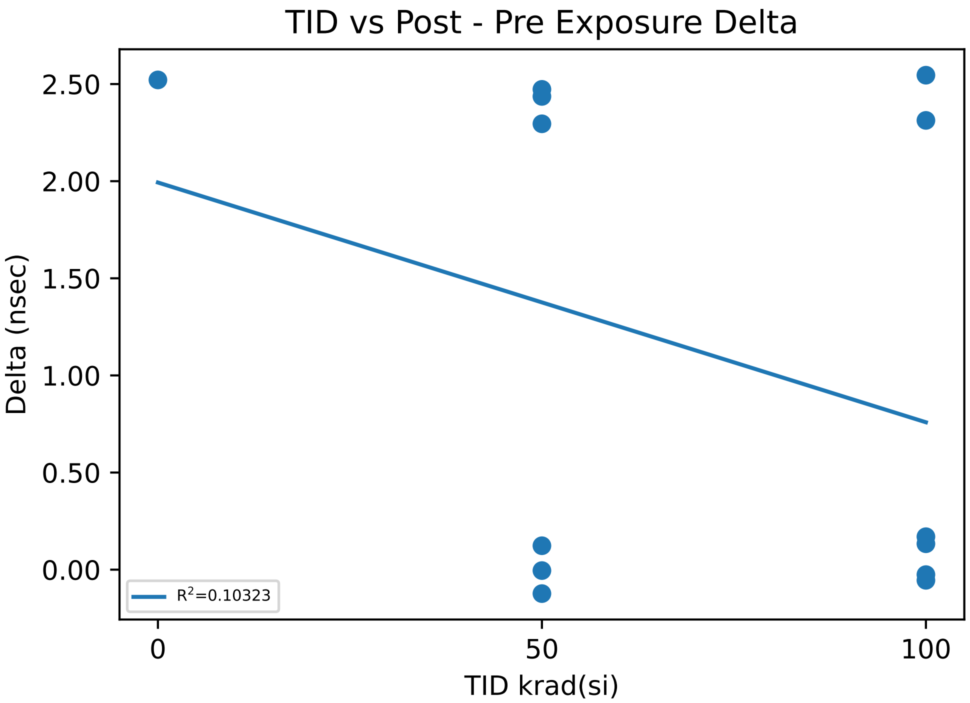


Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.784	31.784	31.784		31.247	31.247	31.247		-0.5376	-0.5376	-0.5376	
50	31.04	31.234	31.433	0.13391	30.354	30.866	31.416	0.53263	-1.0493	-0.3682	0.2619	0.58008
100	30.905	31.191	31.423	0.1772	30.025	30.827	31.332	0.50822	-1.192	-0.36397	-0.0576	0.47496

Device Test: 110.10 Delay Match LO On HO Off IIM Interlock VIN_10V





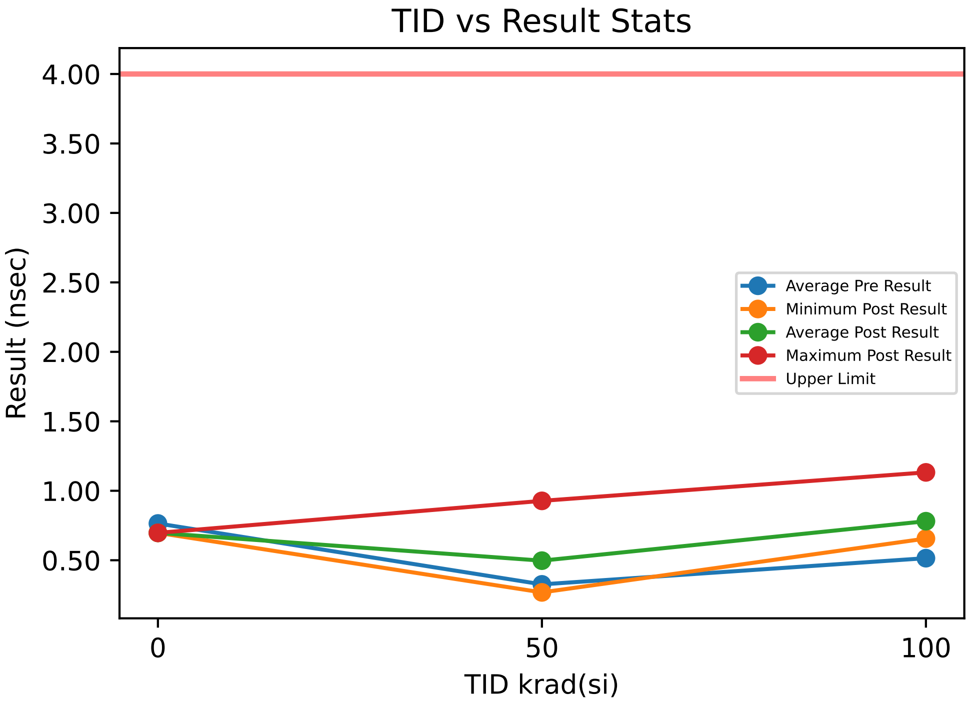
Test Results (Upper Limit = 12.0 (nsec))

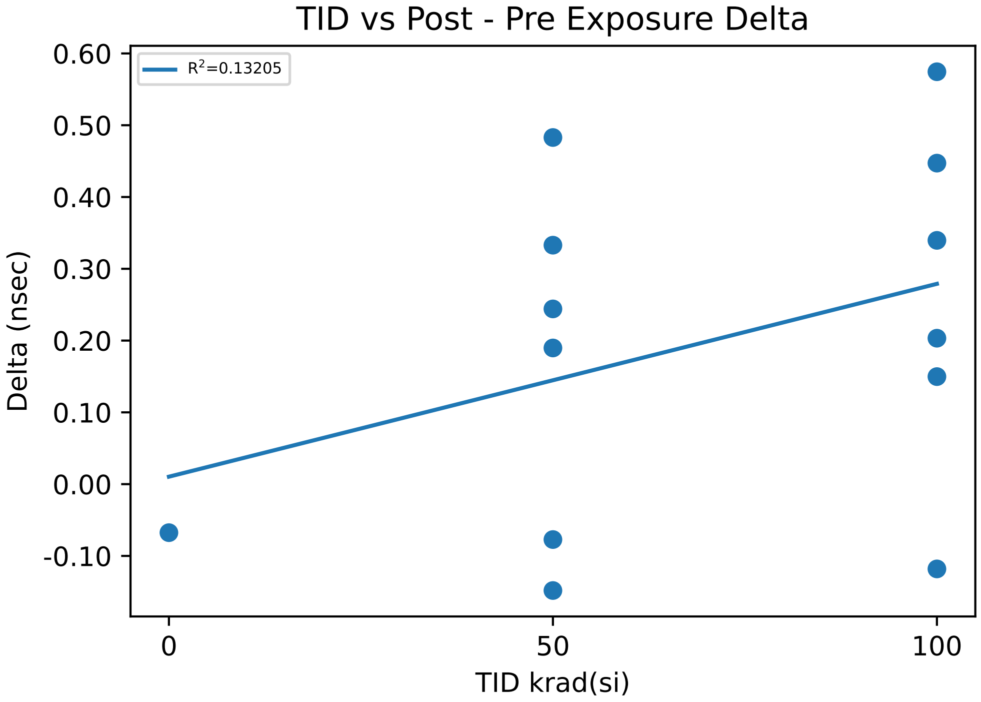
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.9229	4.0461	0.1232
60	50	Biased	3.999	6.2944	2.2954
61	50	Biased	4.158	4.0348	-0.1232
63	100	Biased	4.0885	4.0337	-0.0548
64	100	Biased	3.9717	4.1414	0.1697
65	100	Biased	3.9842	6.5298	2.5456
66	50	Unbiased	3.773	6.2094	2.4364
67	50	Unbiased	3.8831	3.8784	-0.0047
68	50	Unbiased	3.9306	6.4033	2.4727
69	100	Unbiased	3.5862	3.7196	0.1334
70	100	Unbiased	3.7934	6.1063	2.3129
71	100	Unbiased	3.6514	3.6259	-0.0255
72	0	Control	4.2197	6.741	2.5213

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.2197	4.2197	4.2197		6.741	6.741	6.741		2.5213	2.5213	2.5213	
50	3.773	3.9444	4.158	0.12837	3.8784	5.1444	6.4033	1.2714	-0.1232	1.2	2.4727	1.3198
100	3.5862	3.8459	4.0885	0.20092	3.6259	4.6928	6.5298	1.2803	-0.0548	0.84688	2.5456	1.231

Device Test: 110.11 Delay Match LO Off HO On IIM Interlock VIN_10V





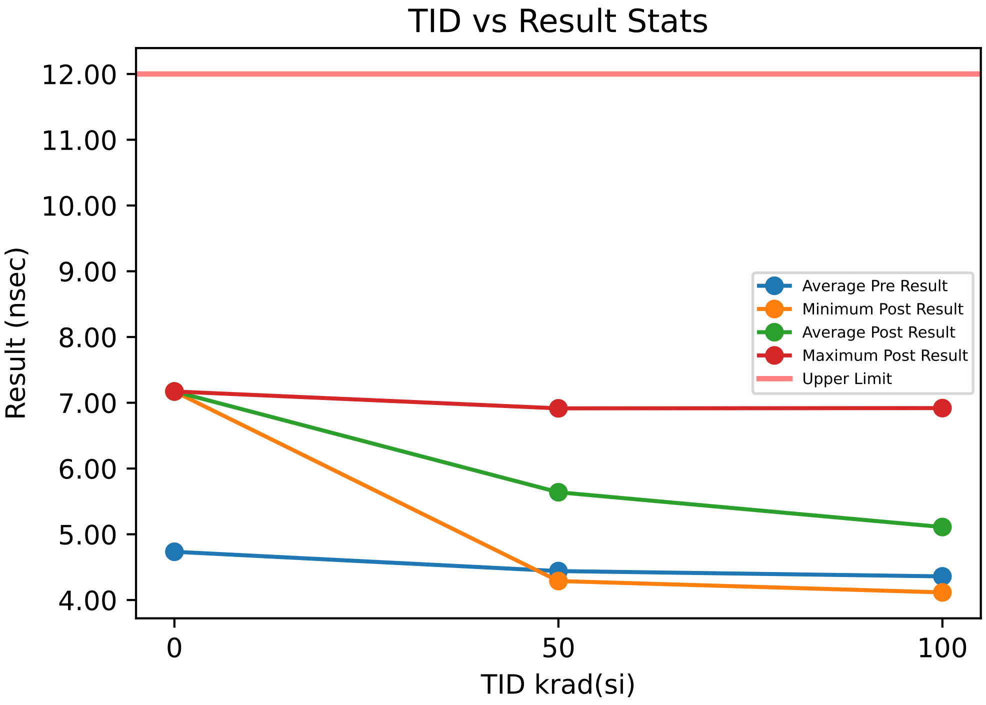
Test Results (Upper Limit = 4.0 (nsec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0277	0.3606	0.3329
60	50	Biased	0.3427	0.5324	0.1897
61	50	Biased	0.1244	0.3685	0.2441
63	100	Biased	0.1876	0.7621	0.5745
64	100	Biased	0.6276	0.7774	0.1498
65	100	Biased	0.4601	0.6634	0.2033
66	50	Unbiased	0.6016	0.5244	-0.0772
67	50	Unbiased	0.4445	0.9274	0.4829
68	50	Unbiased	0.4167	0.2685	-0.1482
69	100	Unbiased	0.3164	0.656	0.3396
70	100	Unbiased	0.8119	0.6938	-0.1181
71	100	Unbiased	0.6852	1.1324	0.4472
72	0	Control	0.7646	0.697	-0.0676

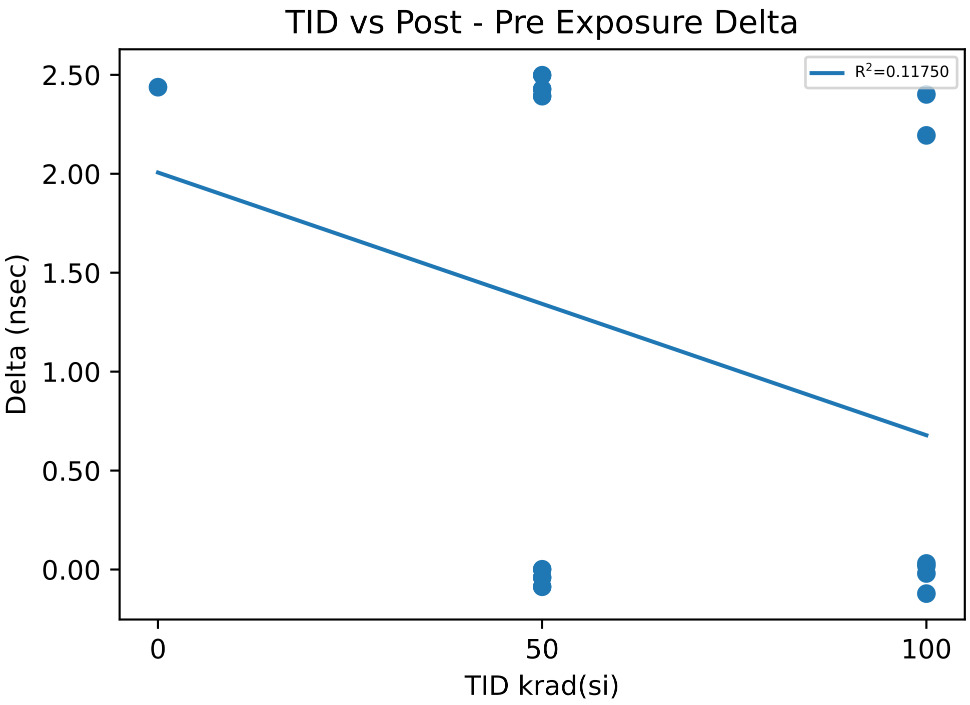
Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.7646	0.7646	0.7646		0.697	0.697	0.697		-0.0676	-0.0676	-0.0676	
50	0.0277	0.32627	0.6016	0.2136	0.2685	0.49697	0.9274	0.23434	-0.1482	0.1707	0.4829	0.24194
100	0.1876	0.5148	0.8119	0.23641	0.656	0.78085	1.1324	0.17939	-0.1181	0.26605	0.5745	0.24429

Device Test: 110.12 Delay Match LO On HO Off IIM Interlock Disable VIN_10V



TID vs Result Stats



TID vs Post - Pre Exposure Delta

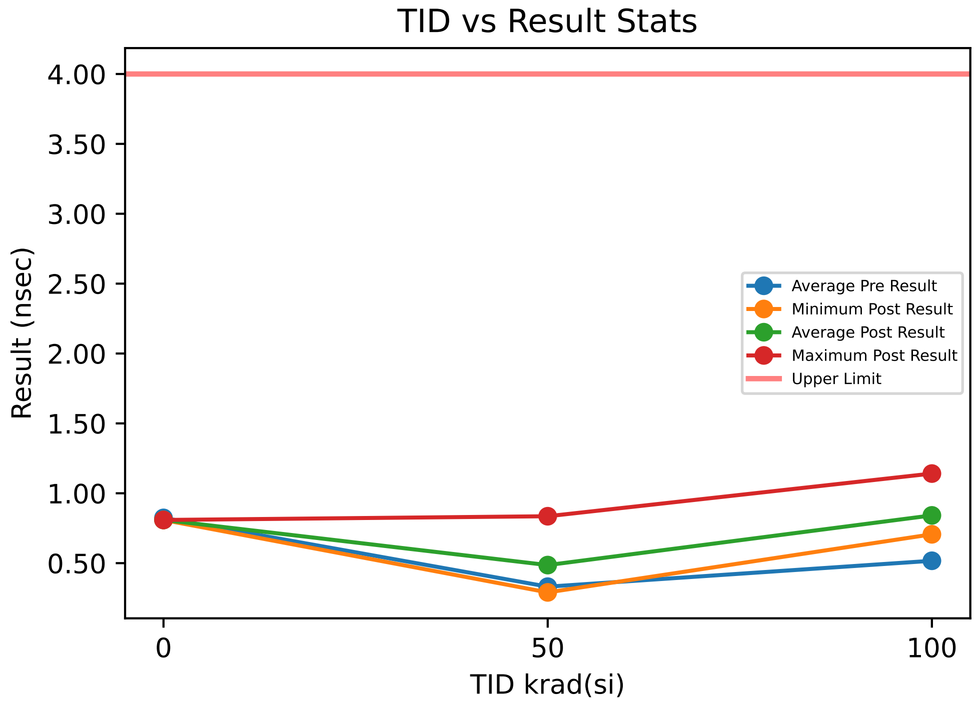
Test Results (Upper Limit = 12.0 (nsec))

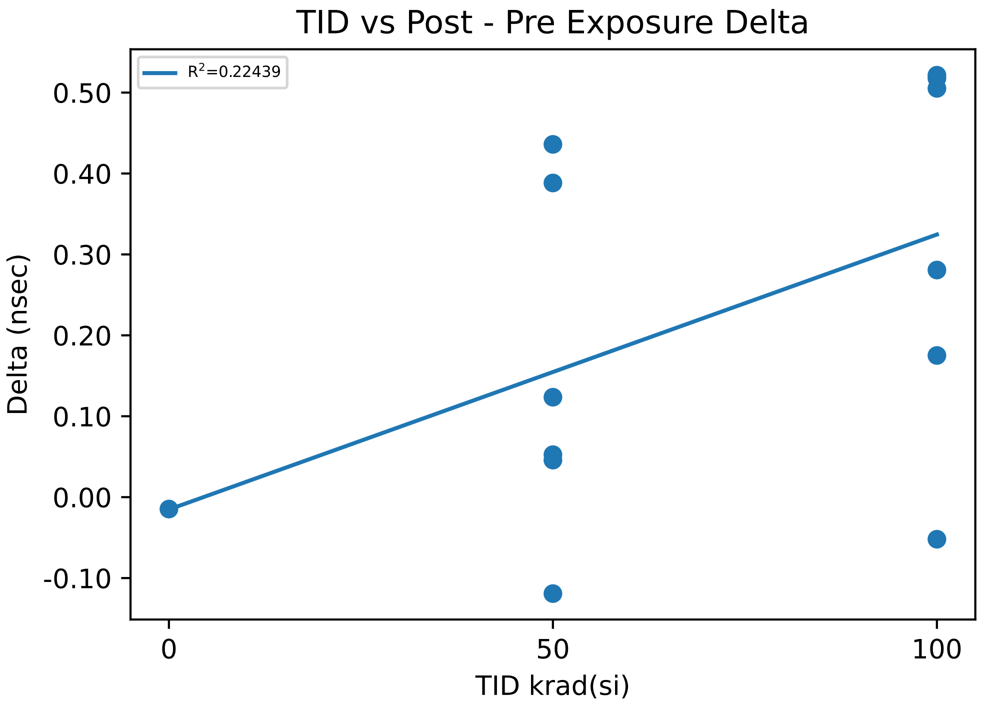
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.4304	4.4317	0.0013
60	50	Biased	4.5229	6.9152	2.3923
61	50	Biased	4.5826	4.5424	-0.0402
63	100	Biased	4.5922	4.4705	-0.1217
64	100	Biased	4.4963	4.4762	-0.0201
65	100	Biased	4.5177	6.9188	2.4011
66	50	Unbiased	4.3166	6.7445	2.4279
67	50	Unbiased	4.3762	4.289	-0.0872
68	50	Unbiased	4.4129	6.9112	2.4983
69	100	Unbiased	4.0853	4.116	0.0307
70	100	Unbiased	4.3267	6.5208	2.1941
71	100	Unbiased	4.1391	4.1583	0.0192
72	0	Control	4.734	7.1717	2.4377

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.734	4.734	4.734		7.1717	7.1717	7.1717		2.4377	2.4377	2.4377	
50	4.3166	4.4403	4.5826	0.097295	4.289	5.639	6.9152	1.3381	-0.0872	1.1987	2.4983	1.3599
100	4.0853	4.3595	4.5922	0.21106	4.116	5.1101	6.9188	1.2623	-0.1217	0.75055	2.4011	1.2013

Device Test: 110.13 Delay Match LO Off HO On IIM Interlock Disable VIN_10V





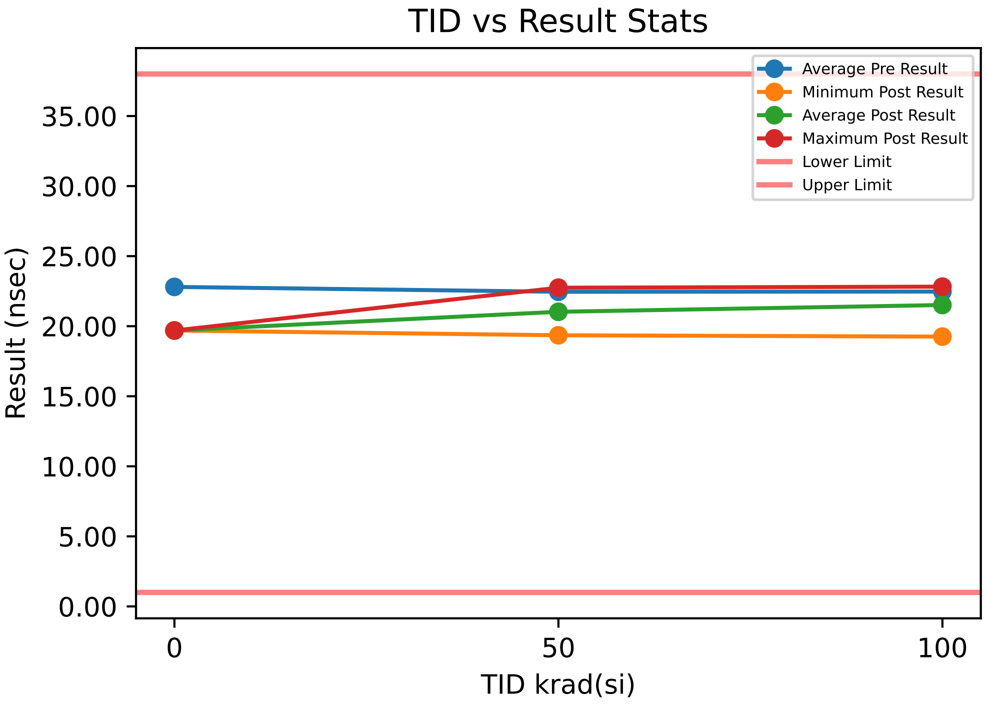
Test Results (Upper Limit = 4.0 (nsec))

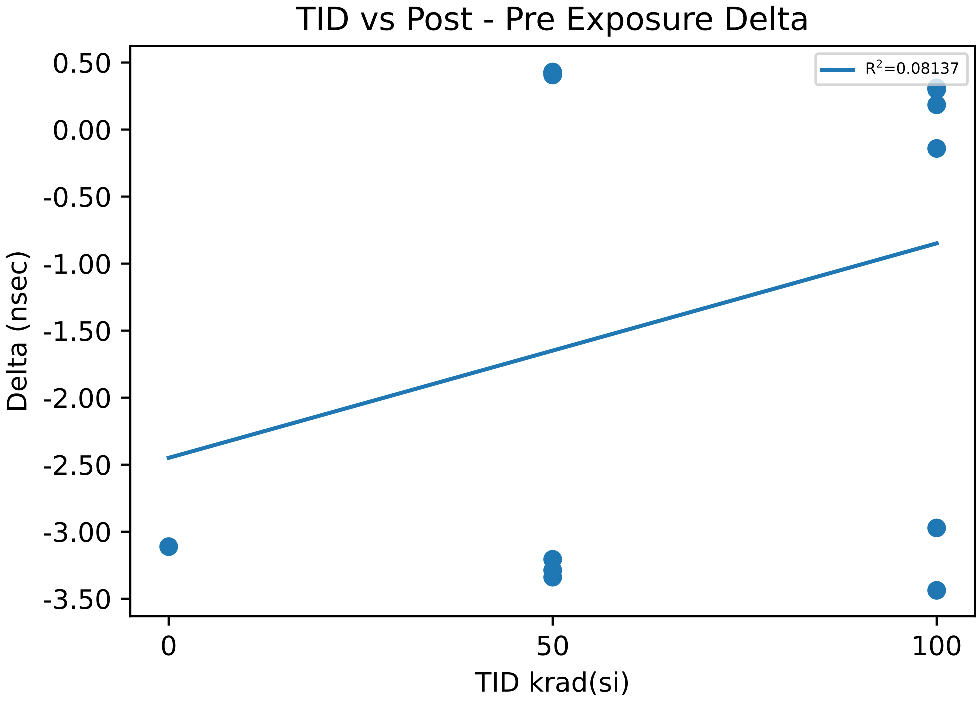
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0215	0.4575	0.436
60	50	Biased	0.3644	0.4102	0.0458
61	50	Biased	0.1897	0.3132	0.1235
63	100	Biased	0.1886	0.7063	0.5177
64	100	Biased	0.6113	0.7864	0.1751
65	100	Biased	0.4919	0.7726	0.2807
66	50	Unbiased	0.5572	0.6097	0.0525
67	50	Unbiased	0.4473	0.8356	0.3883
68	50	Unbiased	0.4099	0.2907	-0.1192
69	100	Unbiased	0.3531	0.8746	0.5215
70	100	Unbiased	0.8212	0.7692	-0.052
71	100	Unbiased	0.6358	1.141	0.5052
72	0	Control	0.8237	0.809	-0.0147

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.8237	0.8237	0.8237		0.809	0.809	0.809		-0.0147	-0.0147	-0.0147	
50	0.0215	0.33167	0.5572	0.1938	0.2907	0.48615	0.8356	0.20595	-0.1192	0.15448	0.436	0.21541
100	0.1886	0.51698	0.8212	0.224	0.7063	0.84168	1.141	0.15626	-0.052	0.3247	0.5215	0.23443

Device Test: 110.2 Prop Delay LO On IIM Interlock VIN_10V





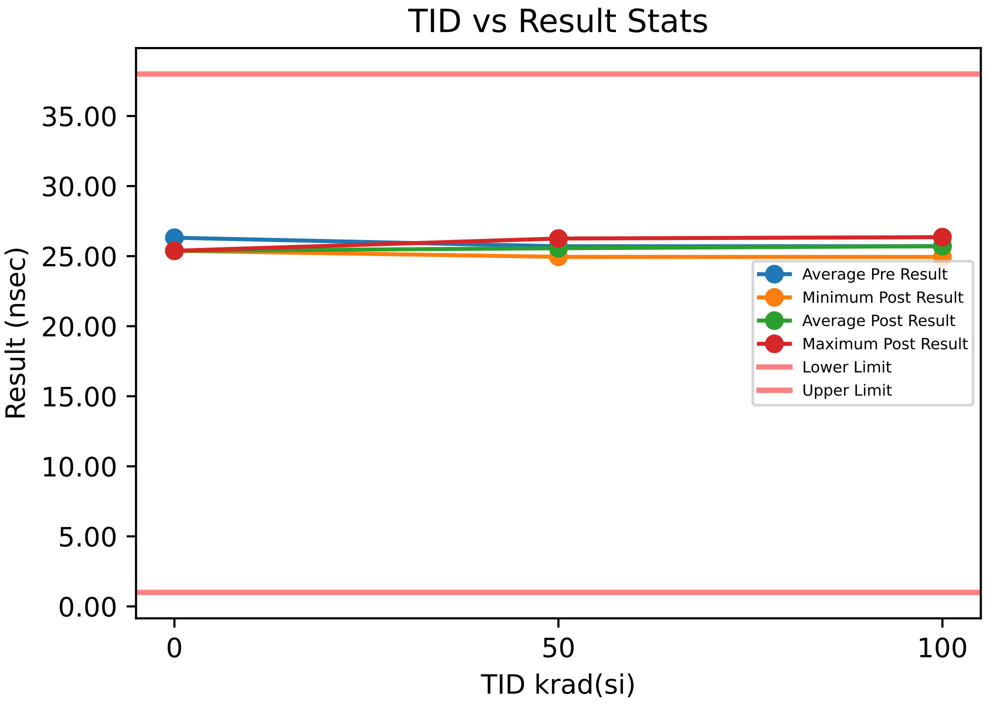
Test Results (Lower Limit = 1.0, Upper Limit = 38.0 (nsec))

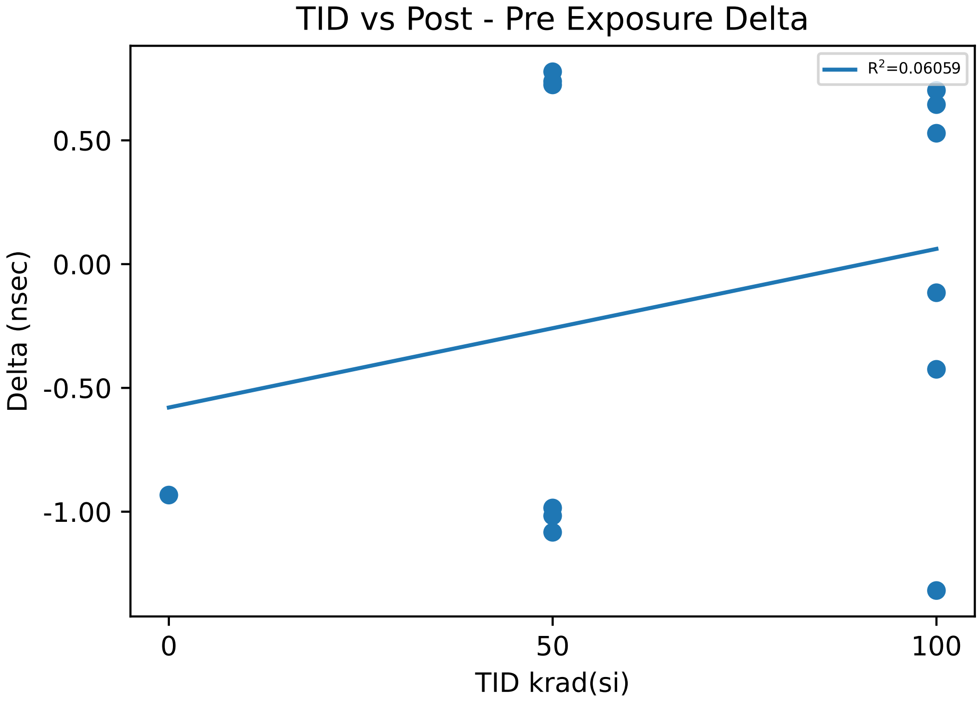
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	22.189	22.615	0.4261
60	50	Biased	22.712	19.372	-3.3395
61	50	Biased	22.101	22.531	0.4297
63	100	Biased	22.212	22.511	0.2992
64	100	Biased	22.762	22.621	-0.141
65	100	Biased	22.228	19.256	-2.972
66	50	Unbiased	22.758	19.552	-3.2062
67	50	Unbiased	22.34	22.747	0.4069
68	50	Unbiased	22.64	19.352	-3.2875
69	100	Unbiased	22.332	22.516	0.1845
70	100	Unbiased	22.777	19.34	-3.4377
71	100	Unbiased	22.51	22.822	0.3115
72	0	Control	22.804	19.692	-3.1115

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.804	22.804	22.804		19.692	19.692	19.692		-3.1115	-3.1115	-3.1115	
50	22.101	22.457	22.758	0.28327	19.352	21.028	22.747	1.7584	-3.3395	-1.4284	0.4297	2.0263
100	22.212	22.47	22.777	0.2552	19.256	21.511	22.822	1.718	-3.4377	-0.95925	0.3115	1.7533

Device Test: 110.3 Prop Delay LO Off IIM Interlock VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

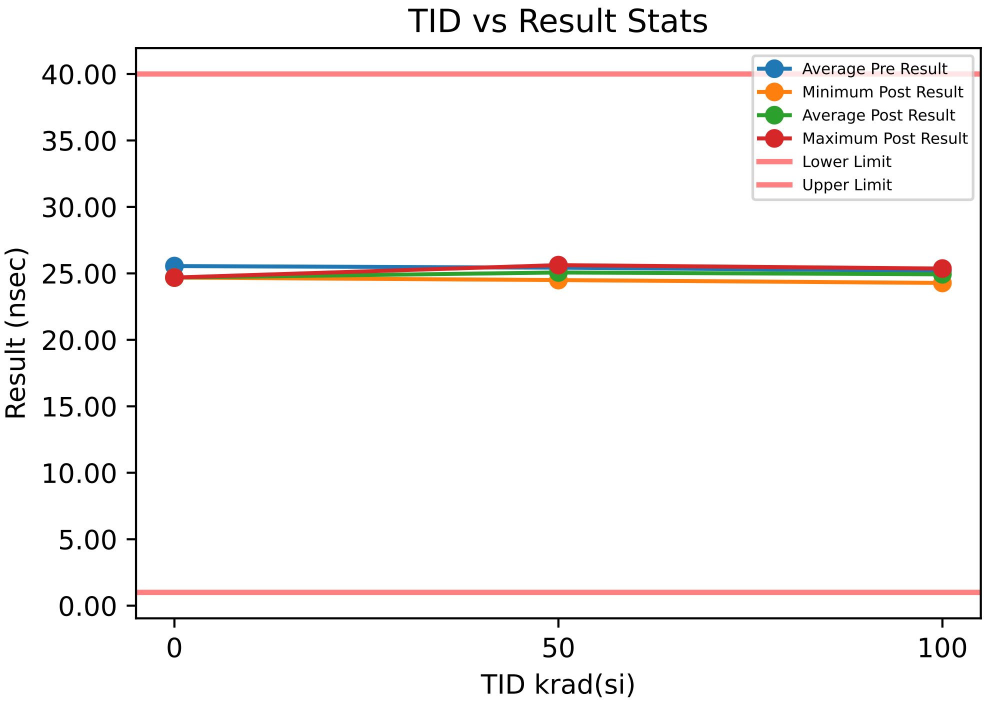
Test Results (Lower Limit = 1.0, Upper Limit = 38.0 (nsec))

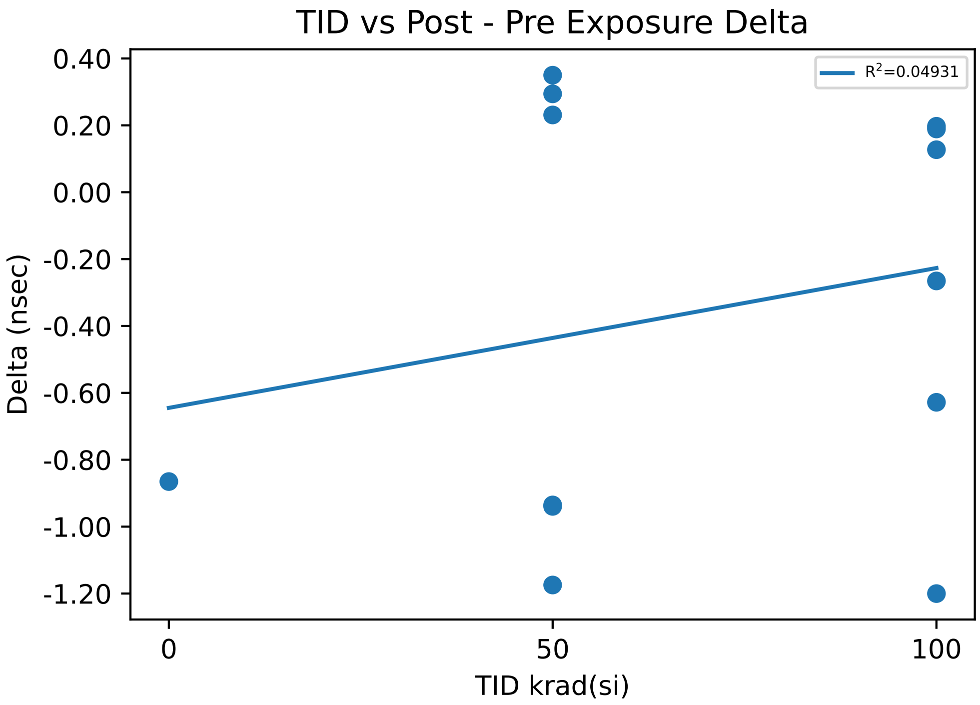
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	25.185	25.923	0.7383
60	50	Biased	26.014	25.029	-0.9849
61	50	Biased	25.266	25.99	0.724
63	100	Biased	25.254	25.955	0.7016
64	100	Biased	26.256	26.141	-0.1155
65	100	Biased	25.369	24.944	-0.4249
66	50	Unbiased	26.246	25.229	-1.0167
67	50	Unbiased	25.48	26.257	0.7771
68	50	Unbiased	26.032	24.948	-1.0833
69	100	Unbiased	25.348	25.877	0.5287
70	100	Unbiased	26.314	24.996	-1.3184
71	100	Unbiased	25.711	26.355	0.6444
72	0	Control	26.316	25.383	-0.9328

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.316	26.316	26.316		25.383	25.383	25.383		-0.9328	-0.9328	-0.9328	
50	25.185	25.704	26.246	0.44911	24.948	25.563	26.257	0.56006	-1.0833	-0.14092	0.7771	0.97275
100	25.254	25.709	26.314	0.47315	24.944	25.711	26.355	0.59778	-1.3184	0.00265	0.7016	0.78981

Device Test: 110.4 Prop Delay HO On IIM Interlock VIN_10V





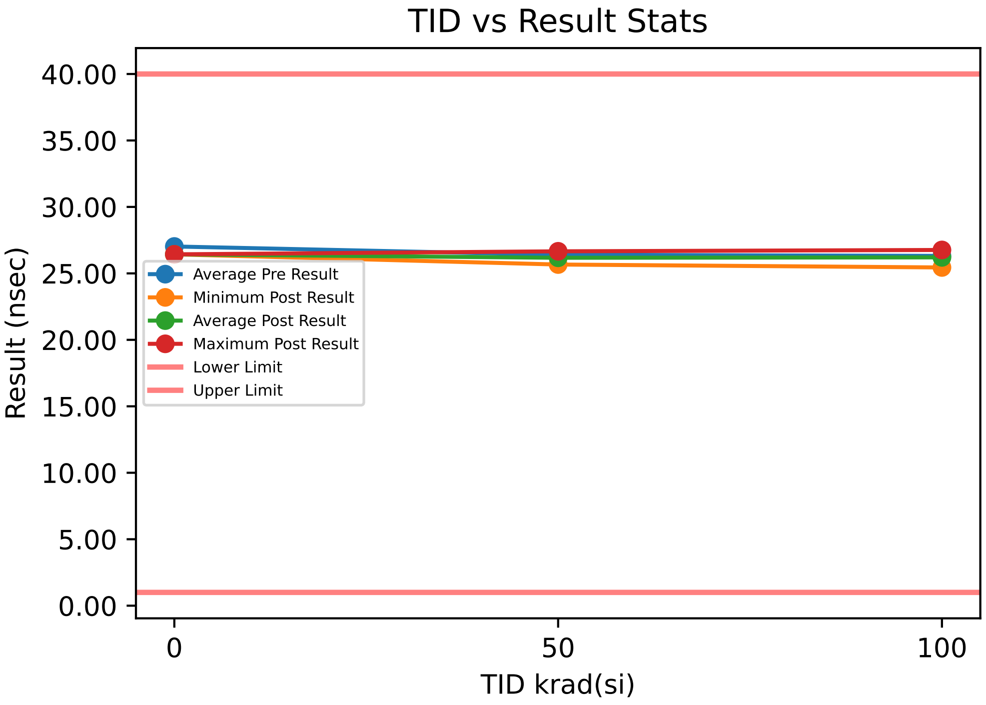
Test Results (Lower Limit = 1.0, Upper Limit = 40.0 (nsec))

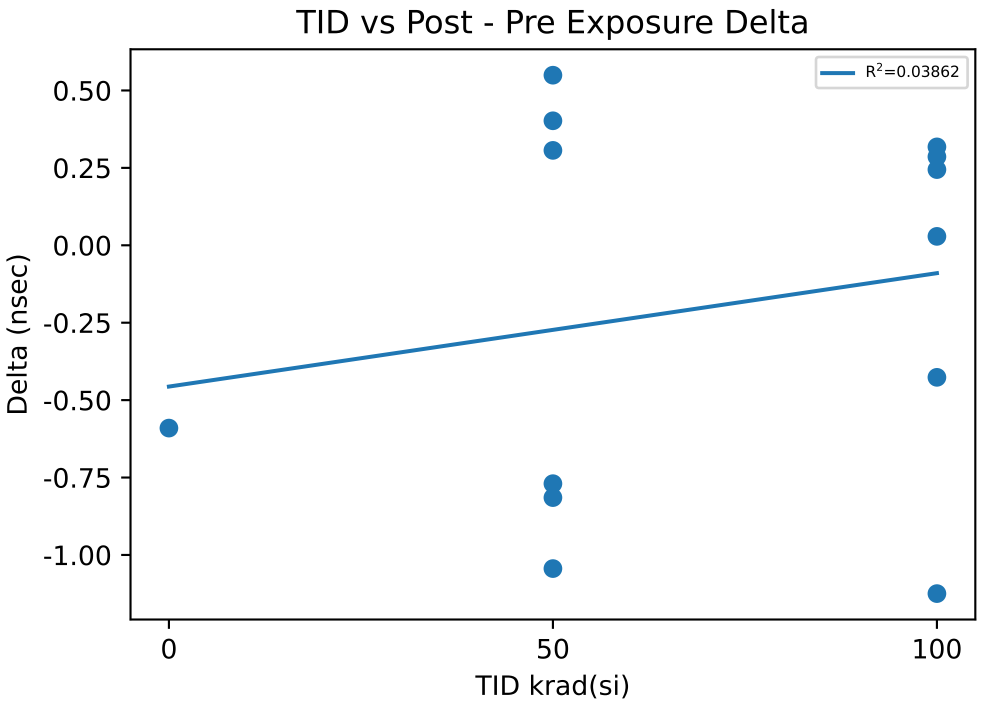
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	25.213	25.563	0.3499
60	50	Biased	25.672	24.497	-1.1745
61	50	Biased	25.39	25.622	0.231
63	100	Biased	25.066	25.193	0.1271
64	100	Biased	25.629	25.363	-0.2653
65	100	Biased	24.909	24.28	-0.6282
66	50	Unbiased	25.644	24.705	-0.9394
67	50	Unbiased	25.036	25.33	0.2941
68	50	Unbiased	25.615	24.68	-0.9351
69	100	Unbiased	25.032	25.221	0.1891
70	100	Unbiased	25.503	24.302	-1.2002
71	100	Unbiased	25.026	25.223	0.1972
72	0	Control	25.551	24.686	-0.8652

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.551	25.551	25.551		24.686	24.686	24.686		-0.8652	-0.8652	-0.8652	
50	25.036	25.428	25.672	0.26176	24.497	25.066	25.622	0.4956	-1.1745	-0.36233	0.3499	0.72262
100	24.909	25.194	25.629	0.29548	24.28	24.93	25.363	0.49871	-1.2002	-0.26338	0.1972	0.56215

Device Test: 110.5 Prop Delay HO Off IIM Interlock VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

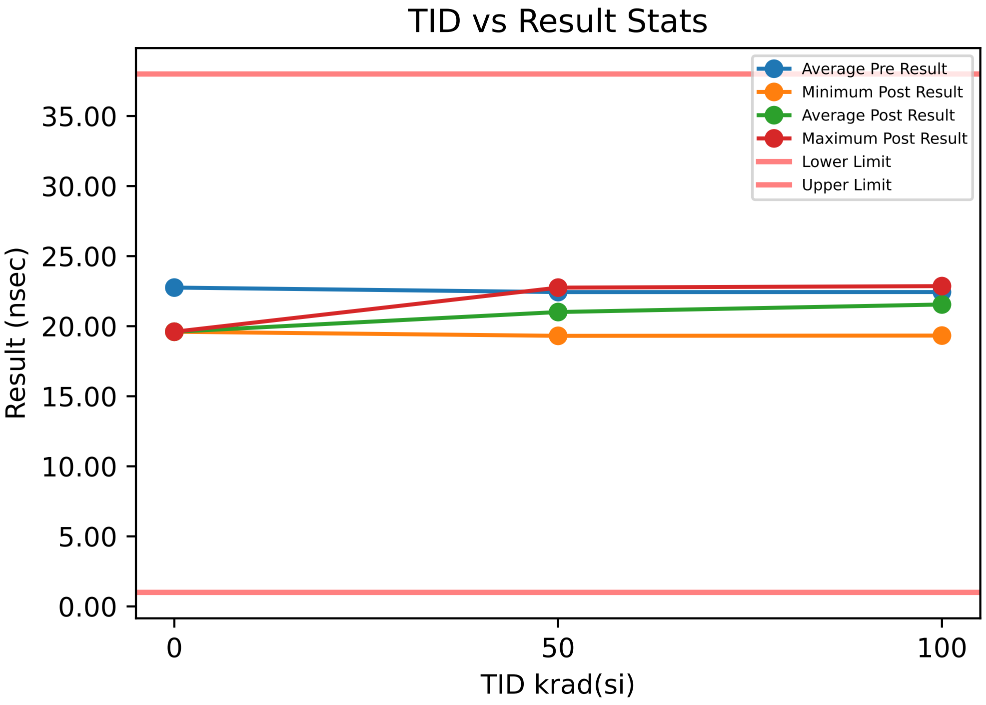
Test Results (Lower Limit = 1.0, Upper Limit = 40.0 (nsec))

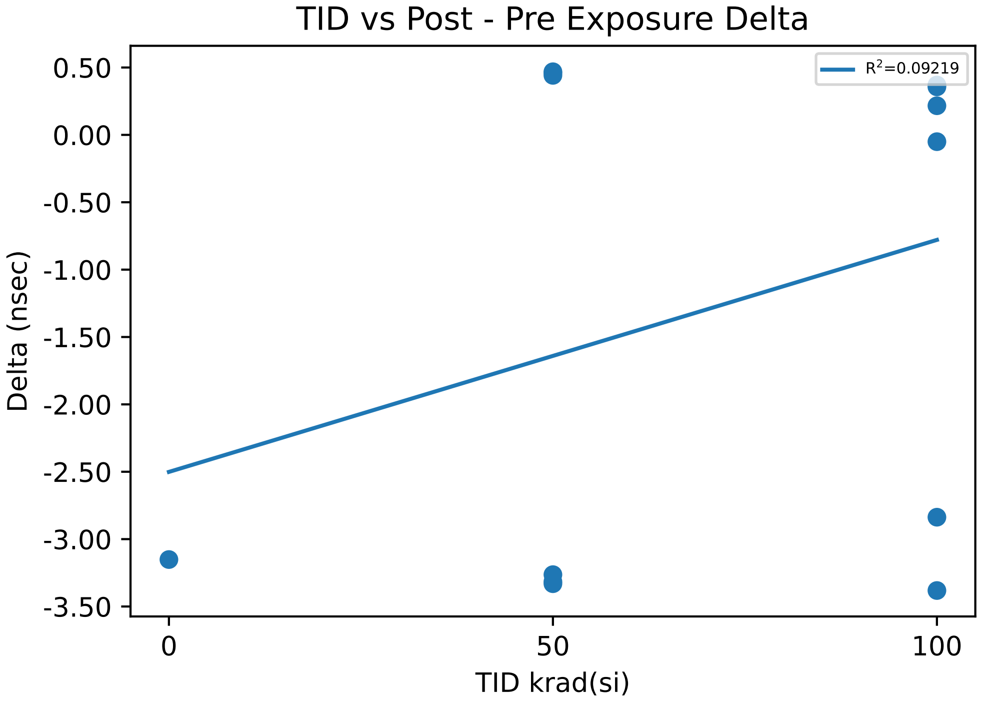
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	26.112	26.661	0.5493
60	50	Biased	26.71	25.666	-1.044
61	50	Biased	26.259	26.566	0.3065
63	100	Biased	26.3	26.544	0.2445
64	100	Biased	26.733	26.762	0.0288
65	100	Biased	26.212	25.786	-0.4264
66	50	Unbiased	26.531	25.762	-0.7698
67	50	Unbiased	26.223	26.625	0.4021
68	50	Unbiased	26.57	25.756	-0.8148
69	100	Unbiased	25.918	26.236	0.3178
70	100	Unbiased	26.571	25.446	-1.1248
71	100	Unbiased	26.161	26.447	0.286
72	0	Control	27.024	26.433	-0.5903

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	27.024	27.024	27.024		26.433	26.433	26.433		-0.5903	-0.5903	-0.5903	
50	26.112	26.401	26.71	0.23535	25.666	26.173	26.661	0.48925	-1.044	-0.22845	0.5493	0.71981
100	25.918	26.316	26.733	0.29412	25.446	26.204	26.762	0.49742	-1.1248	-0.11235	0.3178	0.56827

Device Test: 110.6 Prop Delay LO On IIM Interlock Disable VIN_10V





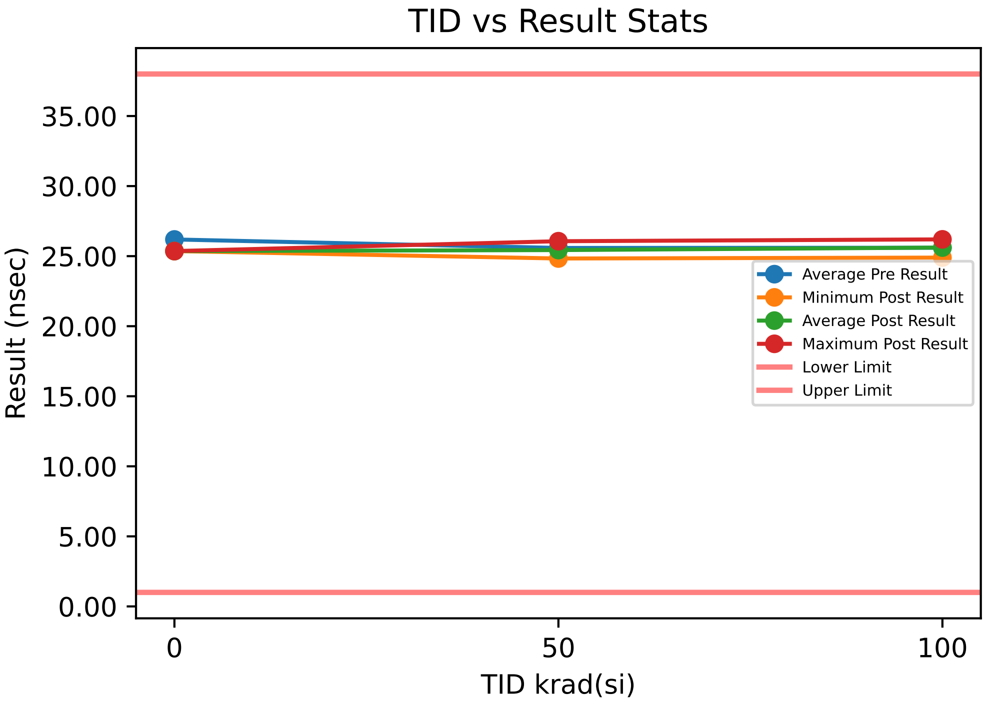
Test Results (Lower Limit = 1.0, Upper Limit = 38.0 (nsec))

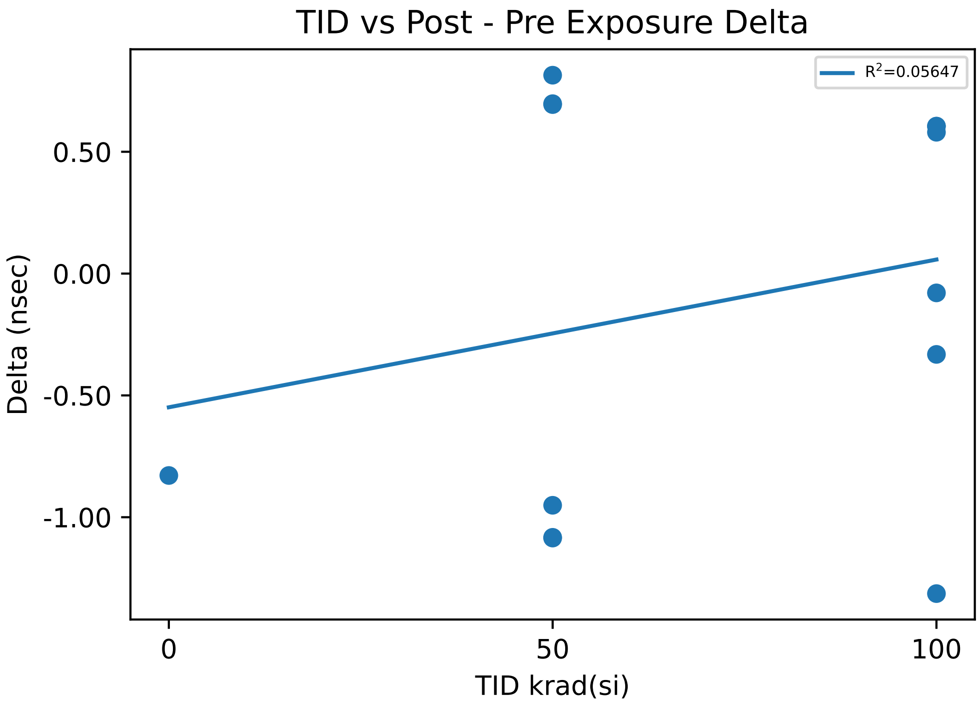
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	22.161	22.629	0.4685
60	50	Biased	22.66	19.344	-3.3156
61	50	Biased	22.121	22.58	0.4591
63	100	Biased	22.169	22.525	0.3565
64	100	Biased	22.73	22.679	-0.0504
65	100	Biased	22.167	19.33	-2.8373
66	50	Unbiased	22.709	19.446	-3.2636
67	50	Unbiased	22.311	22.753	0.4417
68	50	Unbiased	22.642	19.311	-3.3308
69	100	Unbiased	22.299	22.516	0.2163
70	100	Unbiased	22.764	19.382	-3.3814
71	100	Unbiased	22.49	22.86	0.37
72	0	Control	22.755	19.604	-3.1515

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.755	22.755	22.755		19.604	19.604	19.604		-3.1515	-3.1515	-3.1515	
50	22.121	22.434	22.709	0.26756	19.311	21.01	22.753	1.8017	-3.3308	-1.4235	0.4685	2.0594
100	22.167	22.436	22.764	0.26796	19.33	21.549	22.86	1.7032	-3.3814	-0.88772	0.37	1.736

Device Test: 110.7 Prop Delay LO Off IIM Interlock Disable VIN_10V





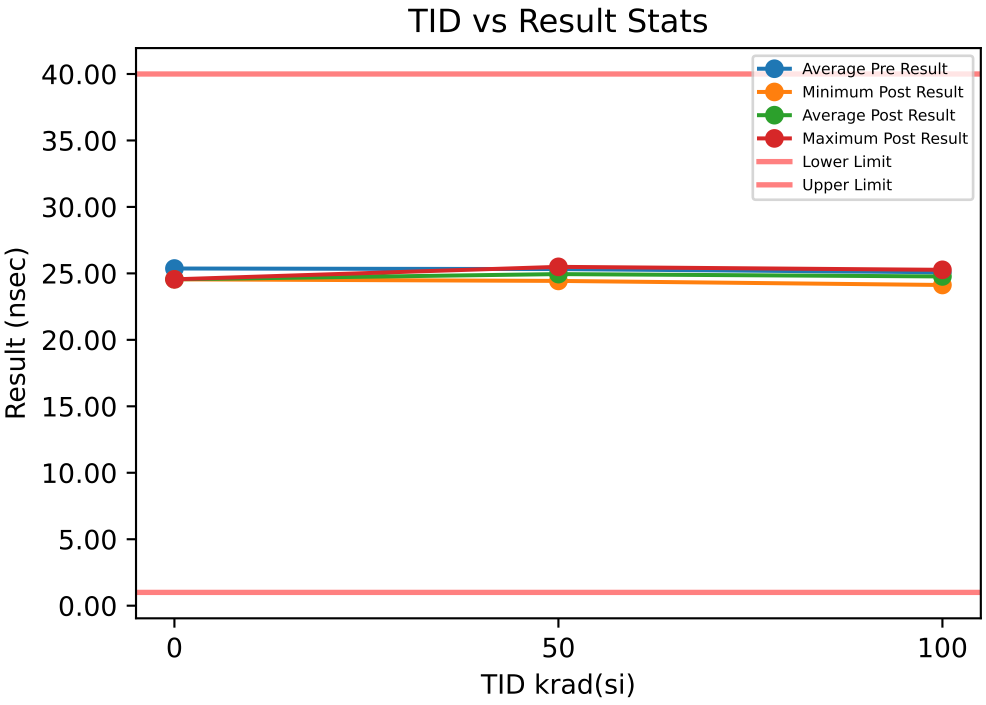
Test Results (Lower Limit = 1.0, Upper Limit = 38.0 (nsec))

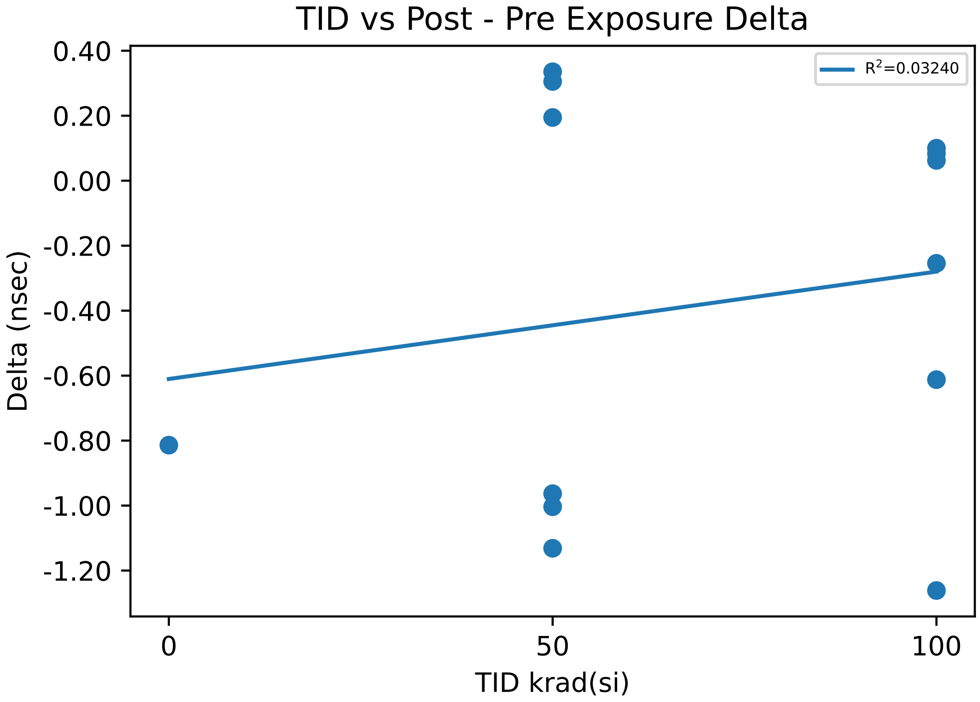
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	25.083	25.897	0.8143
60	50	Biased	25.929	24.843	-1.0855
61	50	Biased	25.108	25.805	0.6974
63	100	Biased	25.149	25.729	0.5801
64	100	Biased	26.134	26.055	-0.0792
65	100	Biased	25.263	24.932	-0.3317
66	50	Unbiased	26.104	25.153	-0.951
67	50	Unbiased	25.372	26.065	0.6937
68	50	Unbiased	25.914	24.832	-1.0825
69	100	Unbiased	25.252	25.857	0.6049
70	100	Unbiased	26.21	24.897	-1.3135
71	100	Unbiased	25.592	26.197	0.6053
72	0	Control	26.19	25.362	-0.8287

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.19	26.19	26.19		25.362	25.362	25.362		-0.8287	-0.8287	-0.8287	
50	25.083	25.585	26.104	0.45213	24.832	25.433	26.065	0.55511	-1.0855	-0.15227	0.8143	0.97428
100	25.149	25.6	26.21	0.46794	24.897	25.611	26.197	0.56331	-1.3135	0.010983	0.6053	0.76285

Device Test: 110.8 Prop Delay HO On IIM Interlock Disable VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

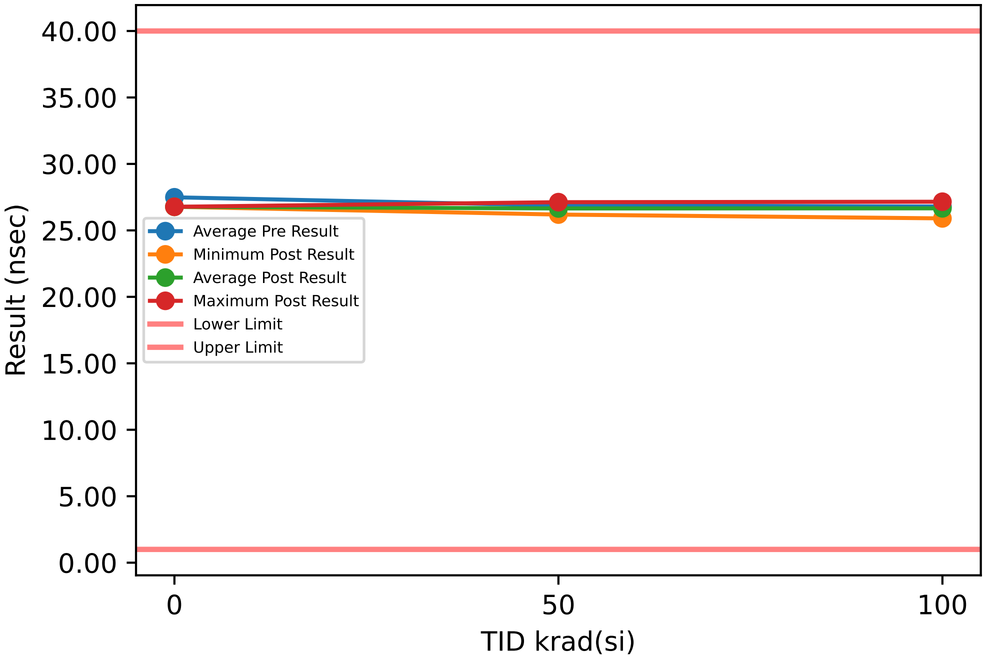
Test Results (Lower Limit = 1.0, Upper Limit = 40.0 (nsec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	25.104	25.439	0.3353
60	50	Biased	25.565	24.433	-1.1314
61	50	Biased	25.297	25.492	0.1945
63	100	Biased	24.96	25.023	0.0624
64	100	Biased	25.523	25.268	-0.2543
65	100	Biased	24.771	24.159	-0.6124
66	50	Unbiased	25.547	24.543	-1.0035
67	50	Unbiased	24.924	25.23	0.3054
68	50	Unbiased	25.504	24.541	-0.9634
69	100	Unbiased	24.899	24.983	0.0834
70	100	Unbiased	25.389	24.128	-1.2614
71	100	Unbiased	24.956	25.056	0.1
72	0	Control	25.367	24.553	-0.814

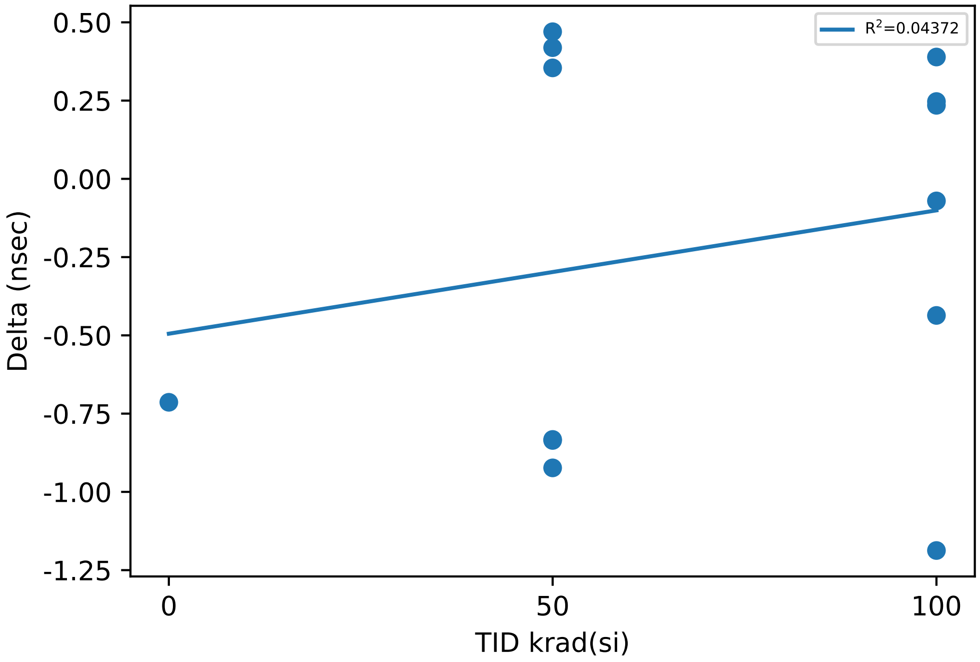
Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.367	25.367	25.367		24.553	24.553	24.553		-0.814	-0.814	-0.814	
50	24.924	25.324	25.565	0.26418	24.433	24.946	25.492	0.4921	-1.1314	-0.37718	0.3353	0.72182
100	24.771	25.083	25.523	0.29957	24.128	24.769	25.268	0.495	-1.2614	-0.31372	0.1	0.54059

Device Test: 110.9 Prop Delay HO Off IIM Interlock Disable VIN_10V



TID vs Result Stats



TID vs Post - Pre Exposure Delta

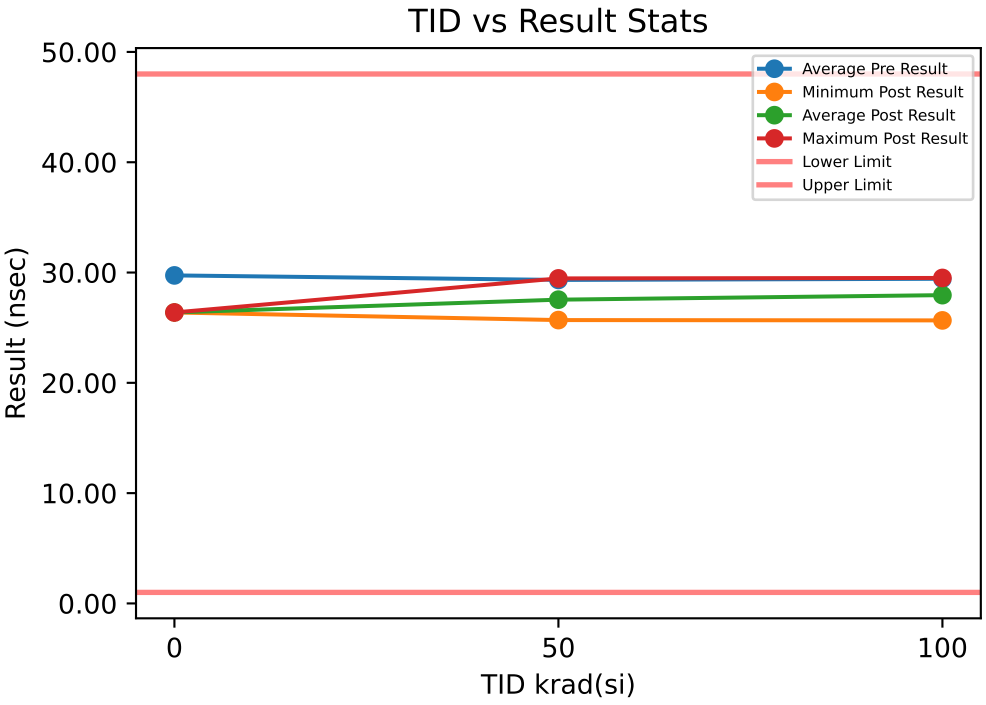
Test Results (Lower Limit = 1.0, Upper Limit = 40.0 (nsec))

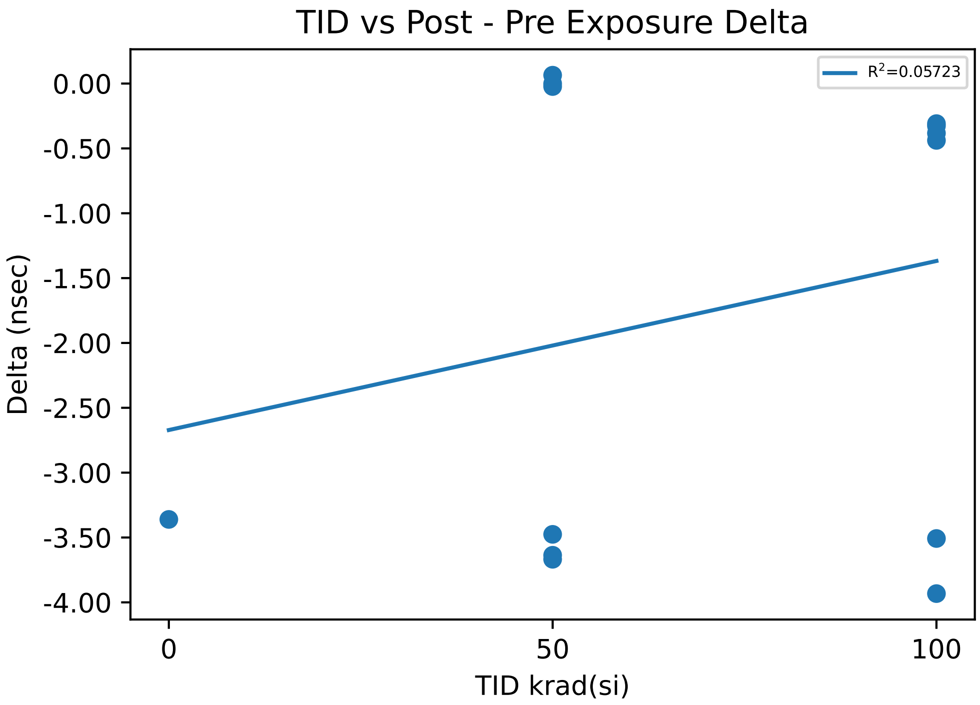
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	26.591	27.061	0.47
60	50	Biased	27.183	26.259	-0.9233
61	50	Biased	26.703	27.122	0.4191
63	100	Biased	26.761	26.996	0.2349
64	100	Biased	27.226	27.155	-0.0705
65	100	Biased	26.685	26.248	-0.4363
66	50	Unbiased	27.026	26.19	-0.8357
67	50	Unbiased	26.687	27.041	0.3545
68	50	Unbiased	27.055	26.222	-0.8325
69	100	Unbiased	26.385	26.632	0.247
70	100	Unbiased	27.09	25.903	-1.1873
71	100	Unbiased	26.63	27.019	0.3892
72	0	Control	27.489	26.775	-0.7138

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	27.489	27.489	27.489		26.775	26.775	26.775		-0.7138	-0.7138	-0.7138	
50	26.591	26.874	27.183	0.24297	26.19	26.649	27.122	0.4674	-0.9233	-0.22465	0.47	0.7019
100	26.385	26.796	27.226	0.3105	25.903	26.659	27.155	0.49601	-1.1873	-0.13717	0.3892	0.59326

Device Test: 111.0 Prop Delay LO Off PWM VIN_12V





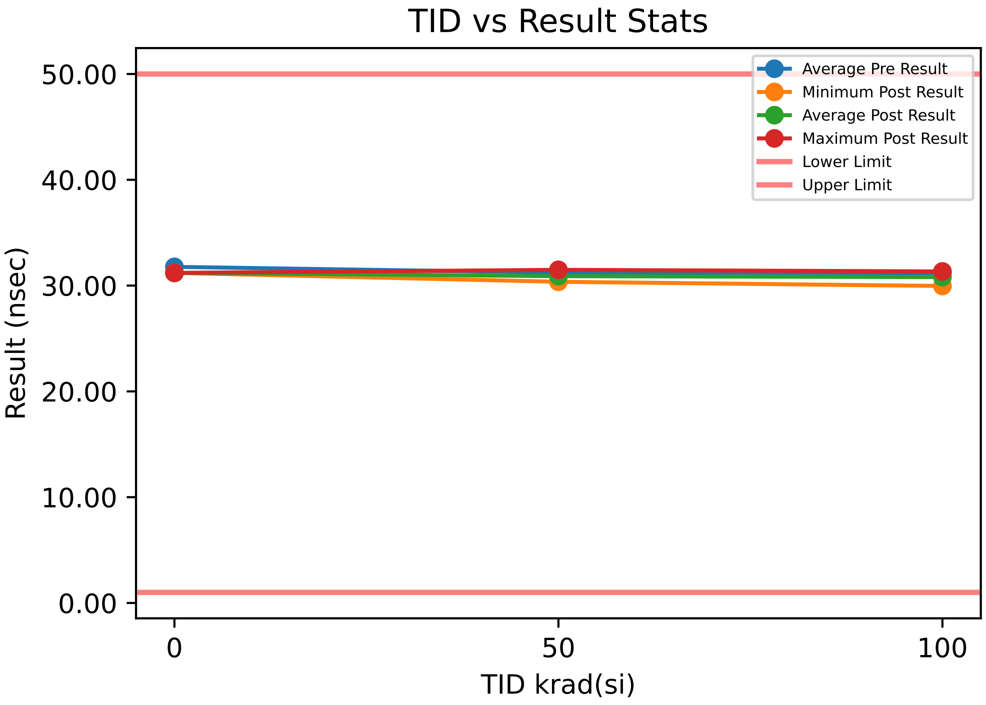
Test Results (Lower Limit = 1.0, Upper Limit = 48.0 (nsec))

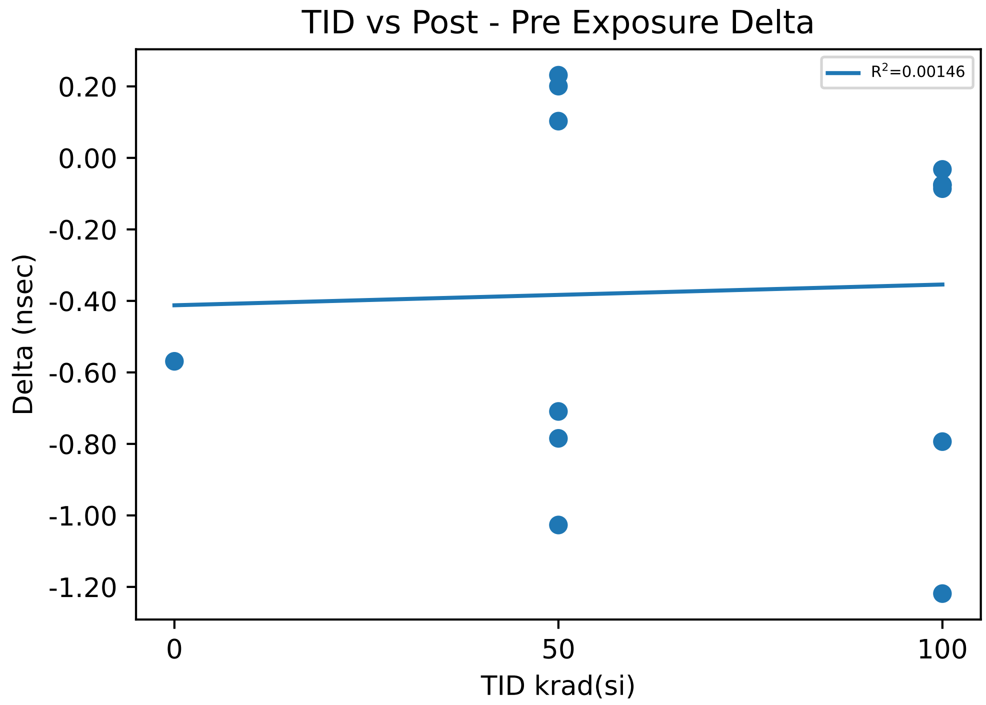
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	29.073	29.137	0.0644
60	50	Biased	29.401	25.764	-3.6369
61	50	Biased	29.172	29.149	-0.023
63	100	Biased	29.078	28.769	-0.3089
64	100	Biased	29.625	29.186	-0.4382
65	100	Biased	29.189	25.682	-3.5077
66	50	Unbiased	29.504	26.028	-3.4757
67	50	Unbiased	29.468	29.468	-0.0008
68	50	Unbiased	29.358	25.69	-3.6679
69	100	Unbiased	29.28	28.897	-0.3829
70	100	Unbiased	29.593	25.66	-3.9325
71	100	Unbiased	29.835	29.509	-0.3264
72	0	Control	29.74	26.379	-3.3606

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	29.74	29.74	29.74		26.379	26.379	26.379		-3.3606	-3.3606	-3.3606	
50	29.073	29.329	29.504	0.17096	25.69	27.539	29.468	1.8826	-3.6679	-1.79	0.0644	1.9769
100	29.078	29.433	29.835	0.29427	25.66	27.951	29.509	1.7841	-3.9325	-1.4828	-0.3089	1.7388

Device Test: 111.1 Prop Delay HO Off PWM VIN_12V





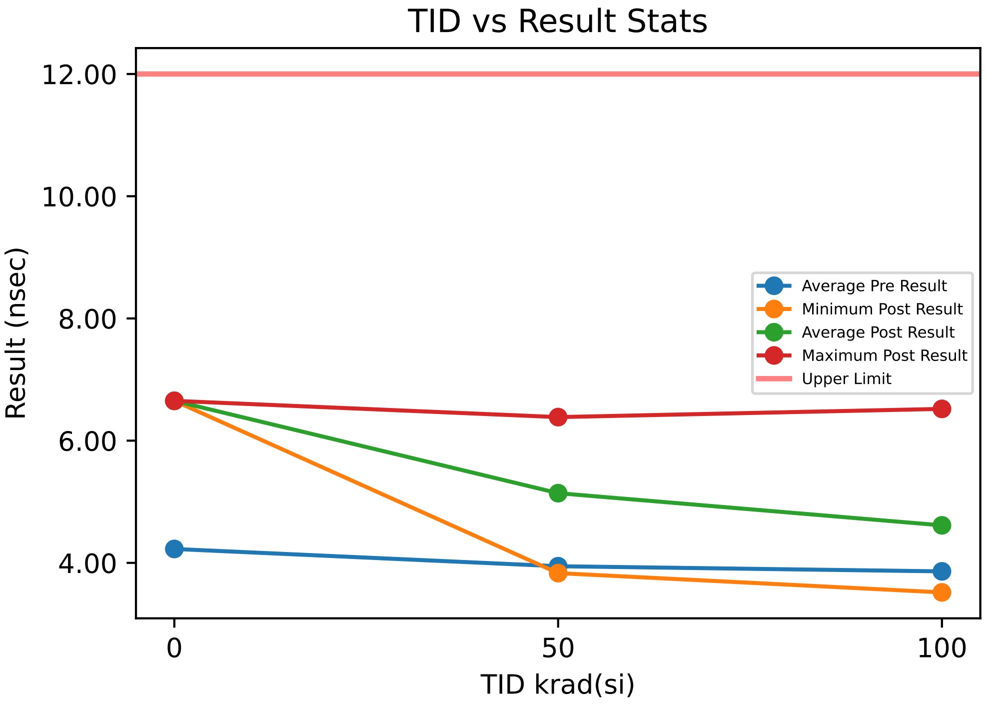
Test Results (Lower Limit = 1.0, Upper Limit = 50.0 (nsec))

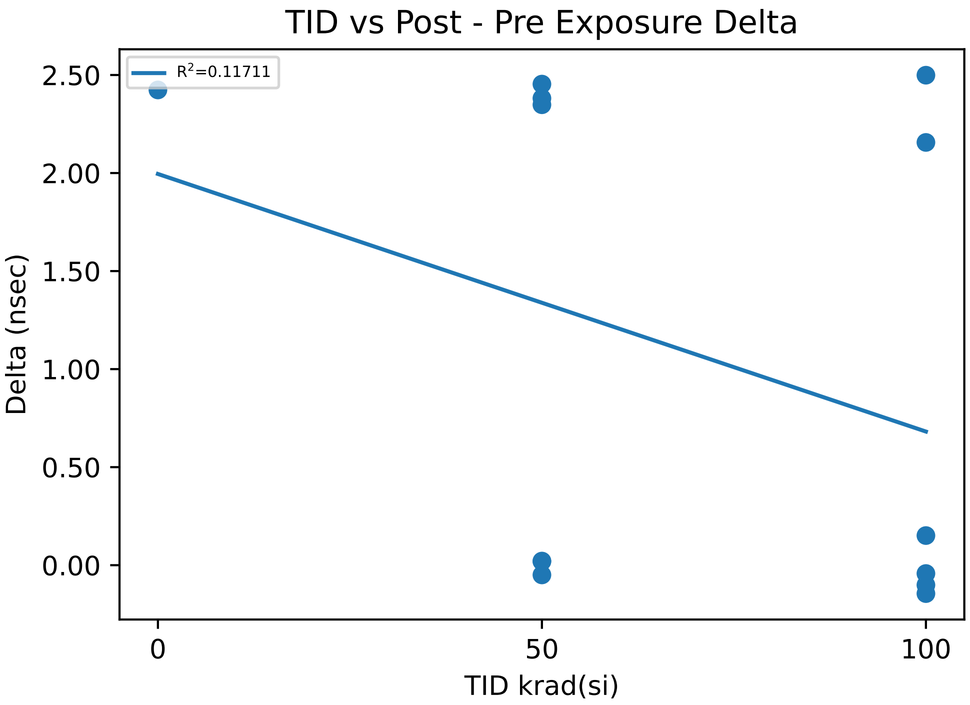
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	31.041	31.272	0.2313
60	50	Biased	31.397	30.37	-1.0268
61	50	Biased	31.238	31.341	0.1028
63	100	Biased	31.132	31.056	-0.0761
64	100	Biased	31.412	31.337	-0.0751
65	100	Biased	31.133	30.339	-0.7936
66	50	Unbiased	31.144	30.36	-0.7845
67	50	Unbiased	31.288	31.489	0.2007
68	50	Unbiased	31.217	30.508	-0.7092
69	100	Unbiased	30.918	30.832	-0.0861
70	100	Unbiased	31.184	29.965	-1.2187
71	100	Unbiased	31.318	31.286	-0.0322
72	0	Control	31.771	31.202	-0.569

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.771	31.771	31.771		31.202	31.202	31.202		-0.569	-0.569	-0.569	
50	31.041	31.221	31.397	0.12169	30.36	30.89	31.489	0.53025	-1.0268	-0.33095	0.2313	0.56919
100	30.918	31.183	31.412	0.17091	29.965	30.802	31.337	0.5478	-1.2187	-0.3803	-0.0322	0.50342

Device Test: 111.10 Delay Match LO On HO Off IIM Interlock VIN_12V





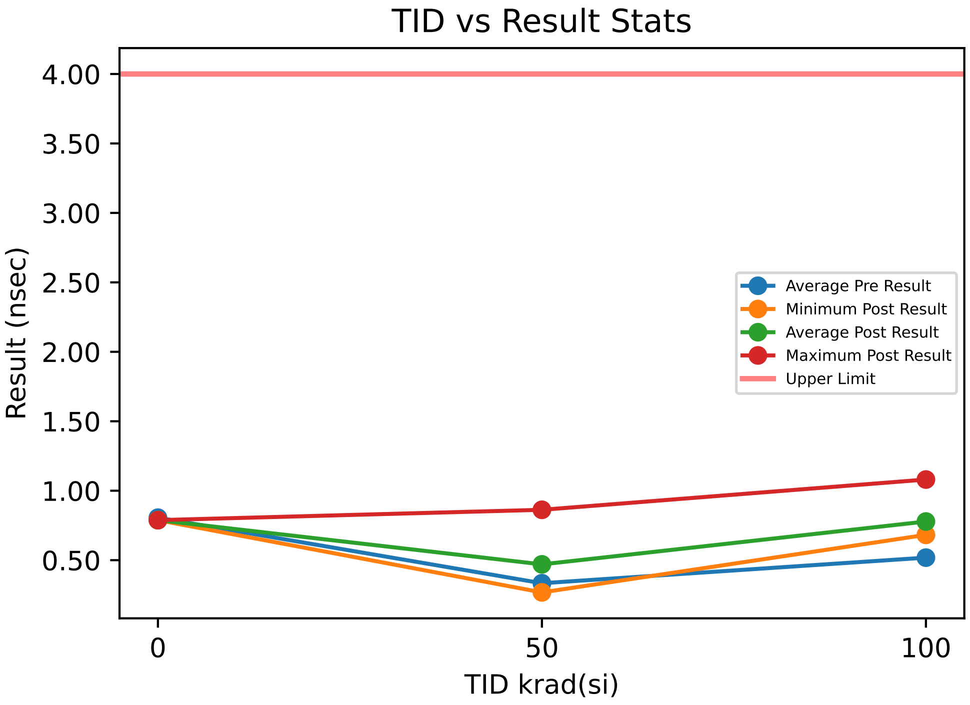
Test Results (Upper Limit = 12.0 (nsec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.9068	3.9261	0.0193
60	50	Biased	4.0371	6.3854	2.3483
61	50	Biased	4.1221	4.1431	0.021
63	100	Biased	4.0895	3.9446	-0.1449
64	100	Biased	3.9568	4.1079	0.1511
65	100	Biased	4.0208	6.5198	2.499
66	50	Unbiased	3.7898	6.2434	2.4536
67	50	Unbiased	3.882	3.8324	-0.0496
68	50	Unbiased	3.933	6.3141	2.3811
69	100	Unbiased	3.6607	3.6182	-0.0425
70	100	Unbiased	3.8212	5.9773	2.1561
71	100	Unbiased	3.6179	3.5169	-0.101
72	0	Control	4.2277	6.6515	2.4238

Test Statistics (nsec)

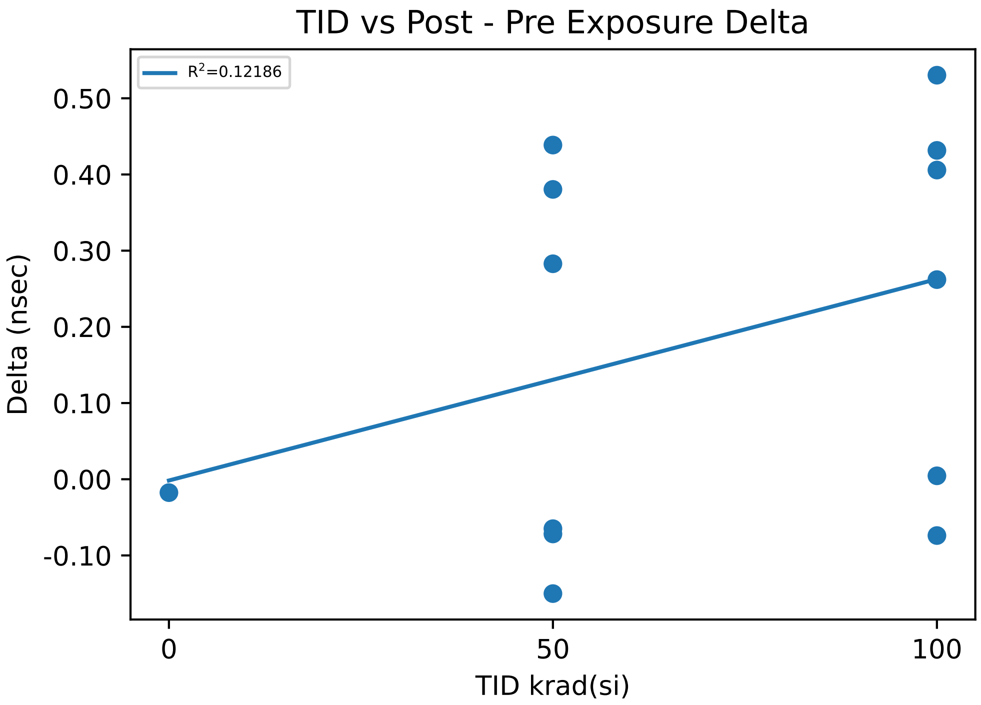
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.2277	4.2277	4.2277		6.6515	6.6515	6.6515		2.4238	2.4238	2.4238	
50	3.7898	3.9451	4.1221	0.1179	3.8324	5.1407	6.3854	1.2903	-0.0496	1.1956	2.4536	1.3138
100	3.6179	3.8611	4.0895	0.19377	3.5169	4.6141	6.5198	1.2954	-0.1449	0.75297	2.499	1.2286

Device Test: 111.11 Delay Match LO Off HO On IIM Interlock VIN_12V


TID vs Result Stats

Test Results (Upper Limit = 4.0 (nsec))

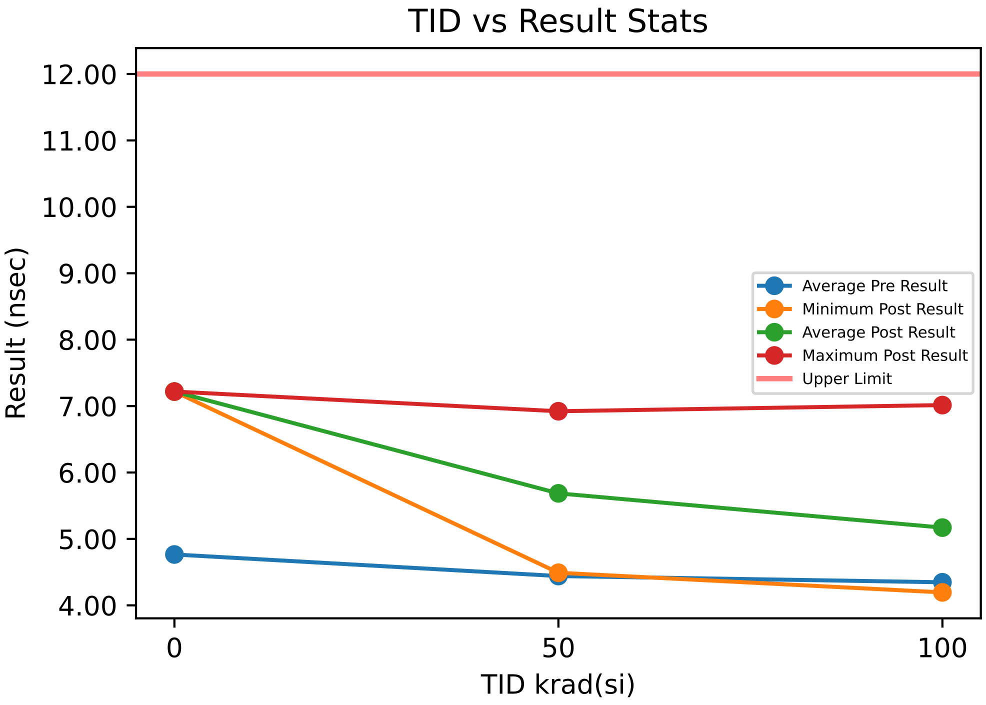
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.044	0.4244	0.3804
60	50	Biased	0.3838	0.3189	-0.0649
61	50	Biased	0.1746	0.4574	0.2828
63	100	Biased	0.1789	0.7092	0.5303
64	100	Biased	0.6777	0.6822	0.0045
65	100	Biased	0.4693	0.7313	0.262
66	50	Unbiased	0.5592	0.4874	-0.0718
67	50	Unbiased	0.424	0.8626	0.4386
68	50	Unbiased	0.4181	0.268	-0.1501
69	100	Unbiased	0.3186	0.7244	0.4058
70	100	Unbiased	0.8159	0.742	-0.0739
71	100	Unbiased	0.6489	1.0805	0.4316
72	0	Control	0.8058	0.7882	-0.0176

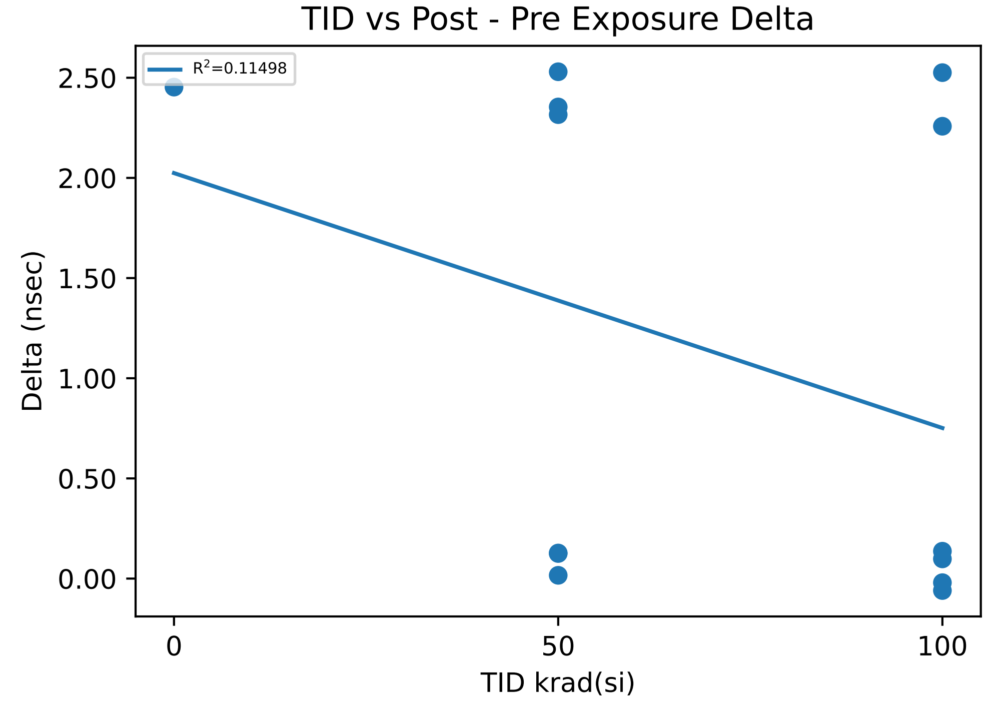

TID vs Post - Pre Exposure Delta

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.8058	0.8058	0.8058		0.7882	0.7882	0.7882		-0.0176	-0.0176	-0.0176	
50	0.044	0.33395	0.5592	0.18861	0.268	0.46978	0.8626	0.20991	-0.1501	0.13583	0.4386	0.26009
100	0.1789	0.51822	0.8159	0.24021	0.6822	0.77827	1.0805	0.14951	-0.0739	0.26005	0.5303	0.24517

Device Test: 111.12 Delay Match LO On HO Off IIM Interlock Disable VIN_12V





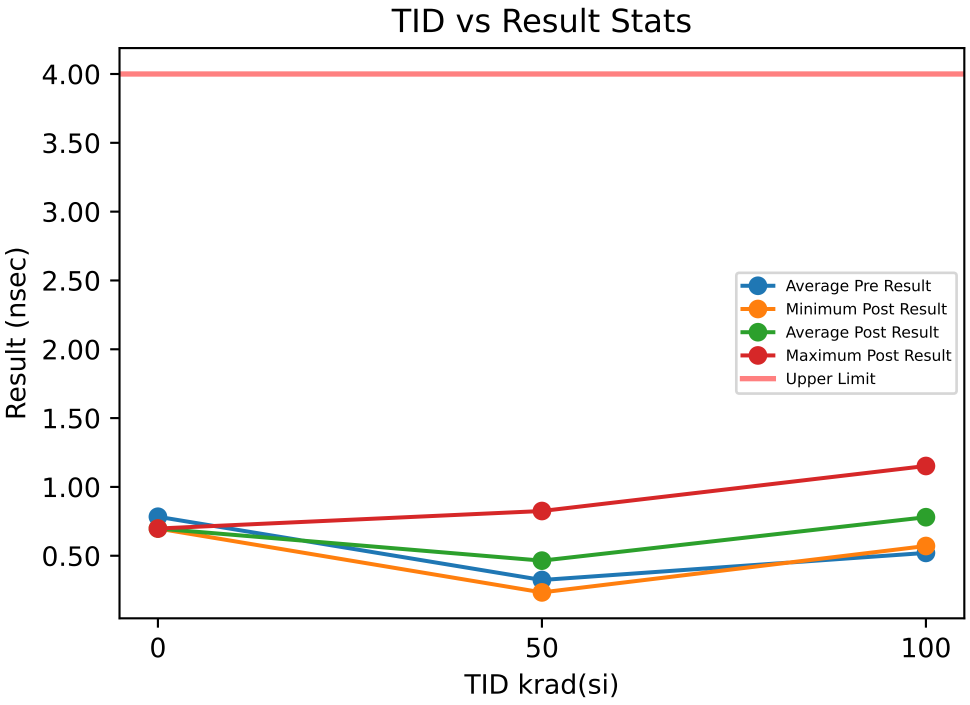
Test Results (Upper Limit = 12.0 (nsec))

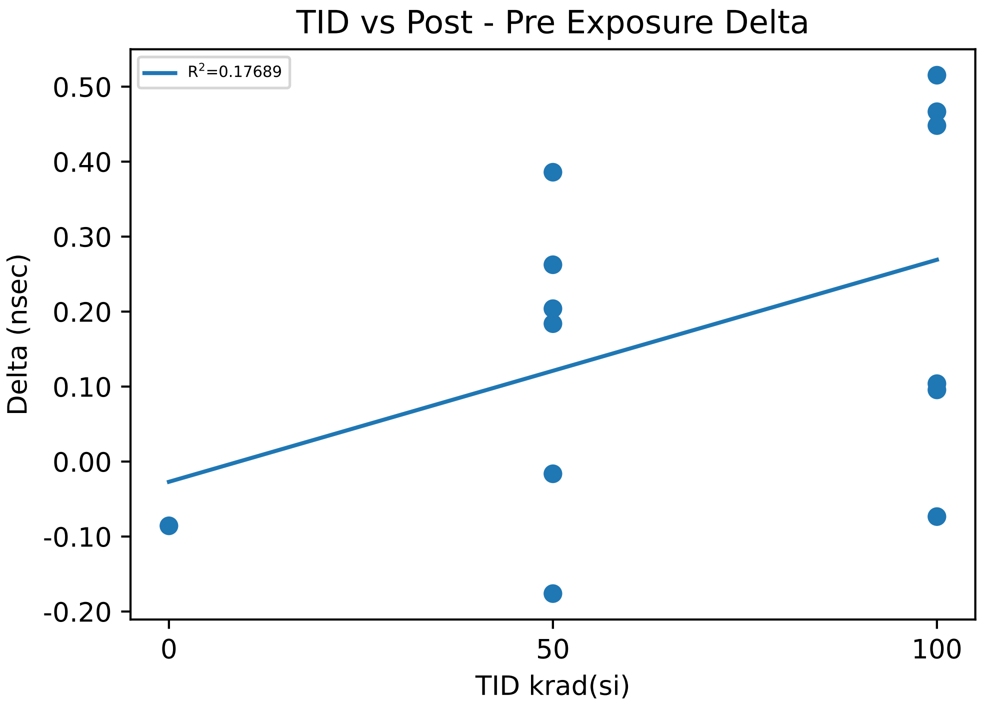
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.4226	4.5502	0.1276
60	50	Biased	4.5396	6.8555	2.3159
61	50	Biased	4.6197	4.636	0.0163
63	100	Biased	4.5842	4.5246	-0.0596
64	100	Biased	4.4973	4.4769	-0.0204
65	100	Biased	4.4895	7.015	2.5255
66	50	Unbiased	4.3074	6.6615	2.3541
67	50	Unbiased	4.3652	4.4904	0.1252
68	50	Unbiased	4.3924	6.9223	2.5299
69	100	Unbiased	4.0965	4.1948	0.0983
70	100	Unbiased	4.3058	6.5637	2.2579
71	100	Unbiased	4.1104	4.247	0.1366
72	0	Control	4.7656	7.2188	2.4532

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.7656	4.7656	4.7656		7.2188	7.2188	7.2188		2.4532	2.4532	2.4532	
50	4.3074	4.4412	4.6197	0.11658	4.4904	5.686	6.9223	1.2385	0.0163	1.2448	2.5299	1.2681
100	4.0965	4.3473	4.5842	0.20956	4.1948	5.1703	7.015	1.2686	-0.0596	0.82305	2.5255	1.2202

Device Test: 111.13 Delay Match LO Off HO On IIM Interlock Disable VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

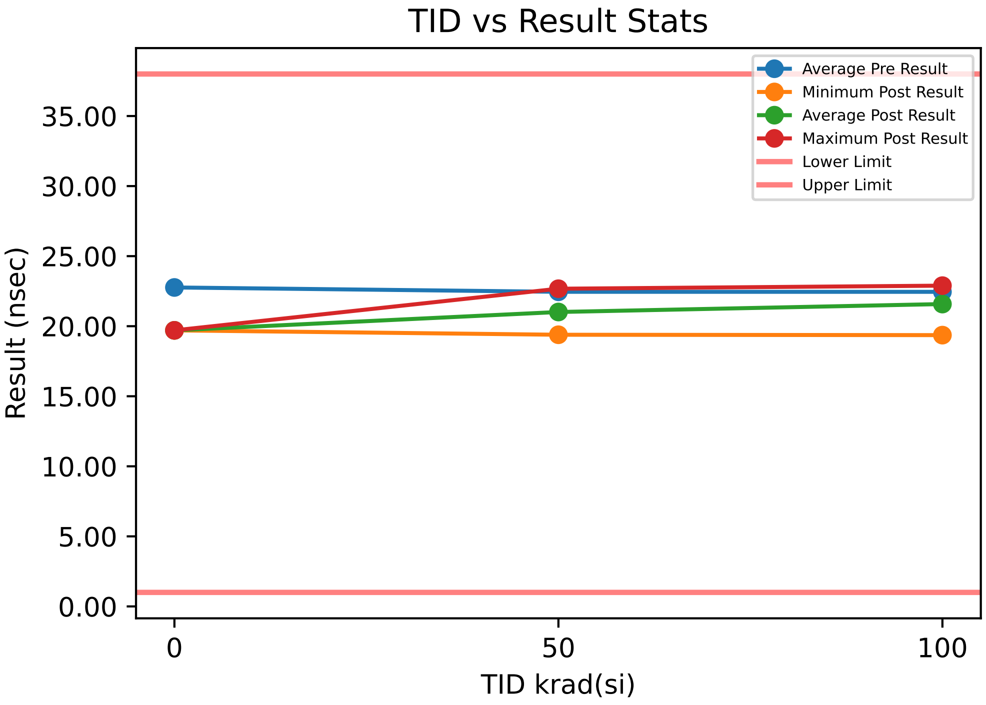
Test Results (Upper Limit = 4.0 (nsec))

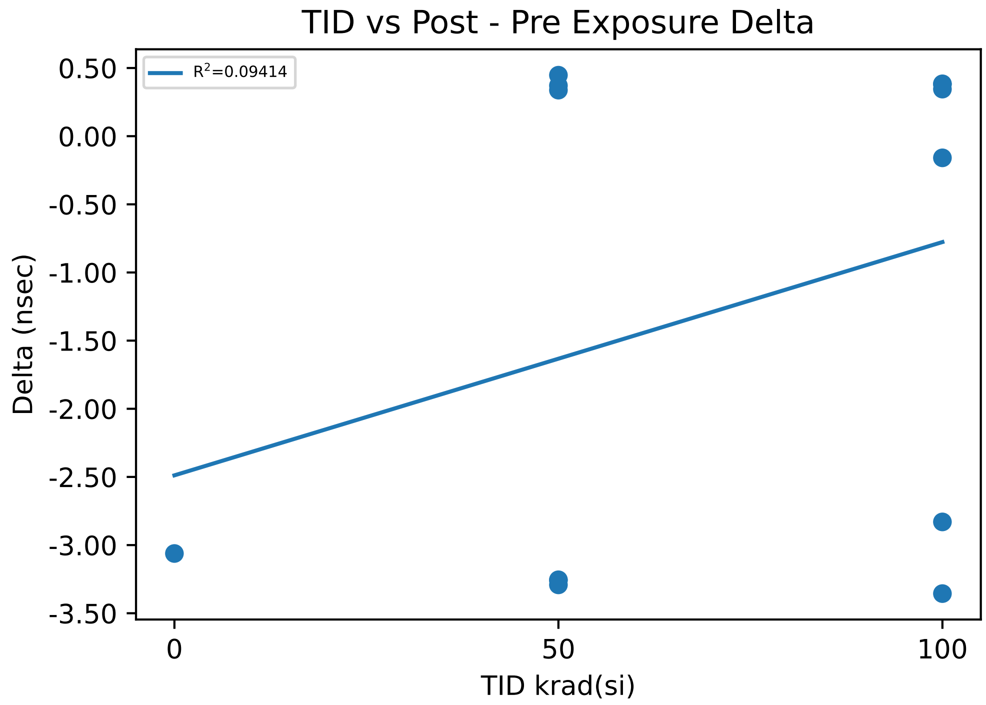
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0498	0.2337	0.1839
60	50	Biased	0.3531	0.557	0.2039
61	50	Biased	0.1339	0.3964	0.2625
63	100	Biased	0.2078	0.7231	0.5153
64	100	Biased	0.6245	0.7201	0.0956
65	100	Biased	0.4669	0.5708	0.1039
66	50	Unbiased	0.5747	0.3986	-0.1761
67	50	Unbiased	0.4391	0.825	0.3859
68	50	Unbiased	0.3919	0.3756	-0.0163
69	100	Unbiased	0.3307	0.7973	0.4666
70	100	Unbiased	0.7899	0.7165	-0.0734
71	100	Unbiased	0.704	1.1521	0.4481
72	0	Control	0.7834	0.6977	-0.0857

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.7834	0.7834	0.7834		0.6977	0.6977	0.6977		-0.0857	-0.0857	-0.0857	
50	0.0498	0.32375	0.5747	0.19641	0.2337	0.46438	0.825	0.20429	-0.1761	0.14063	0.3859	0.20289
100	0.2078	0.52063	0.7899	0.22527	0.5708	0.77998	1.1521	0.19666	-0.0734	0.25935	0.5153	0.2473

Device Test: 111.2 Prop Delay LO On IIM Interlock VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

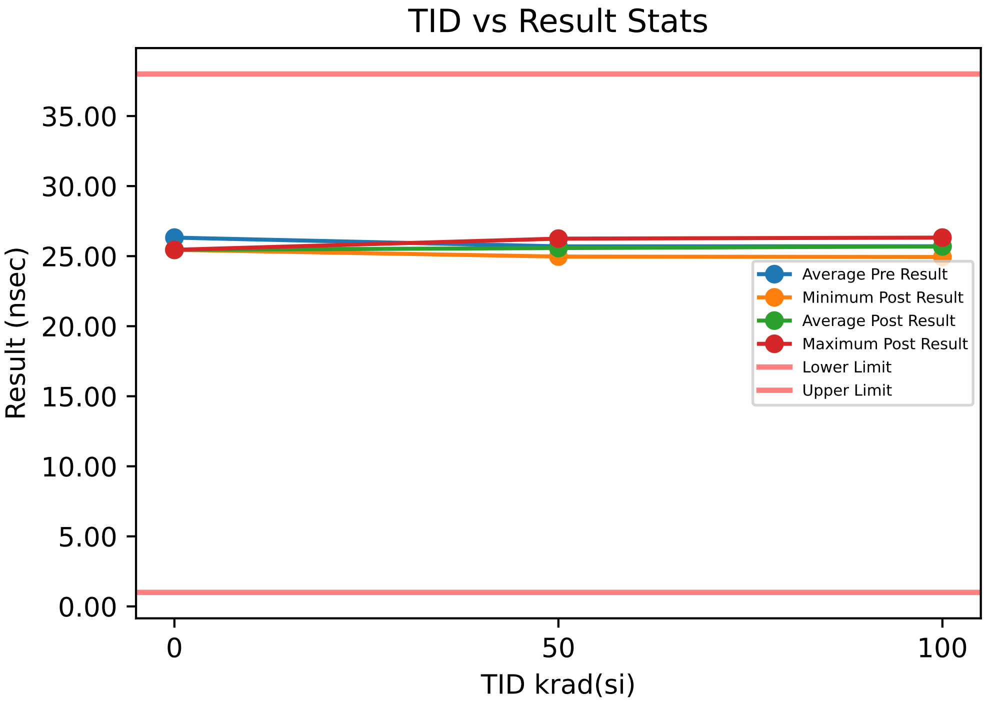
Test Results (Lower Limit = 1.0, Upper Limit = 38.0 (nsec))

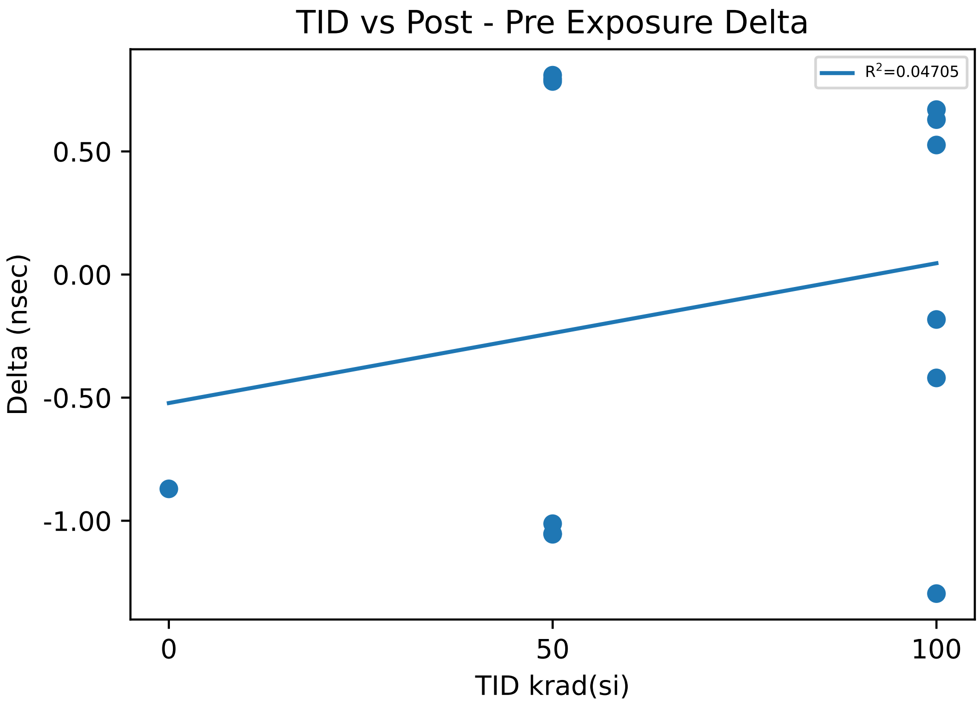
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	22.192	22.639	0.4473
60	50	Biased	22.683	19.424	-3.2583
61	50	Biased	22.134	22.504	0.3708
63	100	Biased	22.204	22.585	0.3811
64	100	Biased	22.781	22.622	-0.159
65	100	Biased	22.192	19.362	-2.83
66	50	Unbiased	22.737	19.446	-3.2918
67	50	Unbiased	22.337	22.674	0.3377
68	50	Unbiased	22.644	19.389	-3.2545
69	100	Unbiased	22.274	22.619	0.3452
70	100	Unbiased	22.753	19.397	-3.3559
71	100	Unbiased	22.509	22.893	0.384
72	0	Control	22.764	19.703	-3.0617

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.764	22.764	22.764		19.703	19.703	19.703		-3.0617	-3.0617	-3.0617	
50	22.134	22.454	22.737	0.26595	19.389	21.013	22.674	1.7462	-3.2918	-1.4415	0.4473	2.0014
100	22.192	22.452	22.781	0.26931	19.362	21.58	22.893	1.7079	-3.3559	-0.87243	0.384	1.7402

Device Test: 111.3 Prop Delay LO Off IIM Interlock VIN_12V





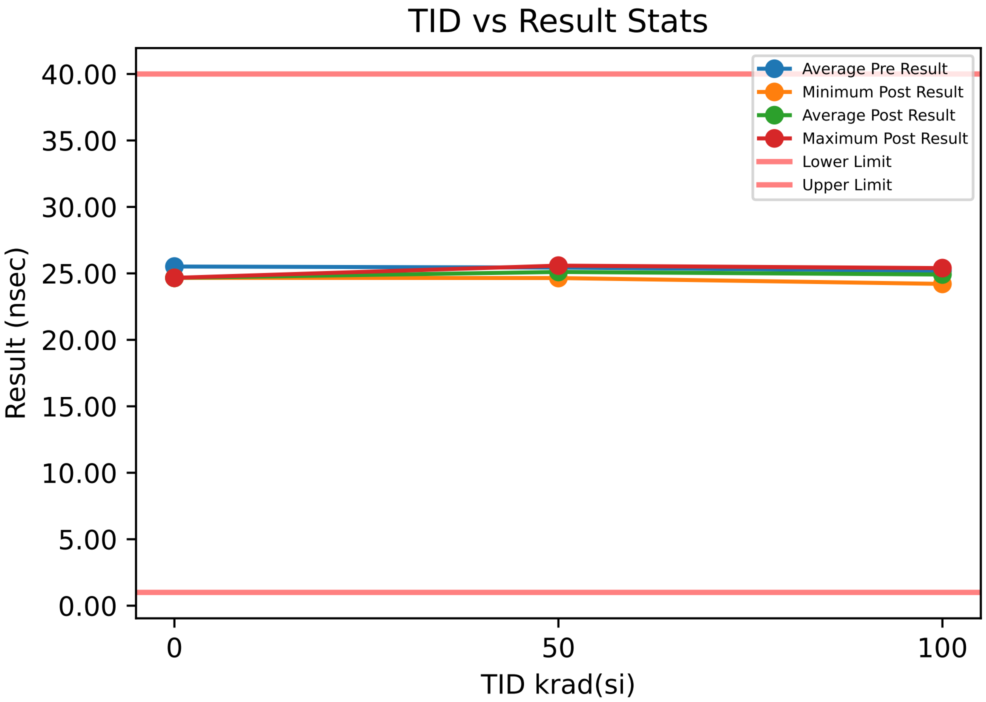
Test Results (Lower Limit = 1.0, Upper Limit = 38.0 (nsec))

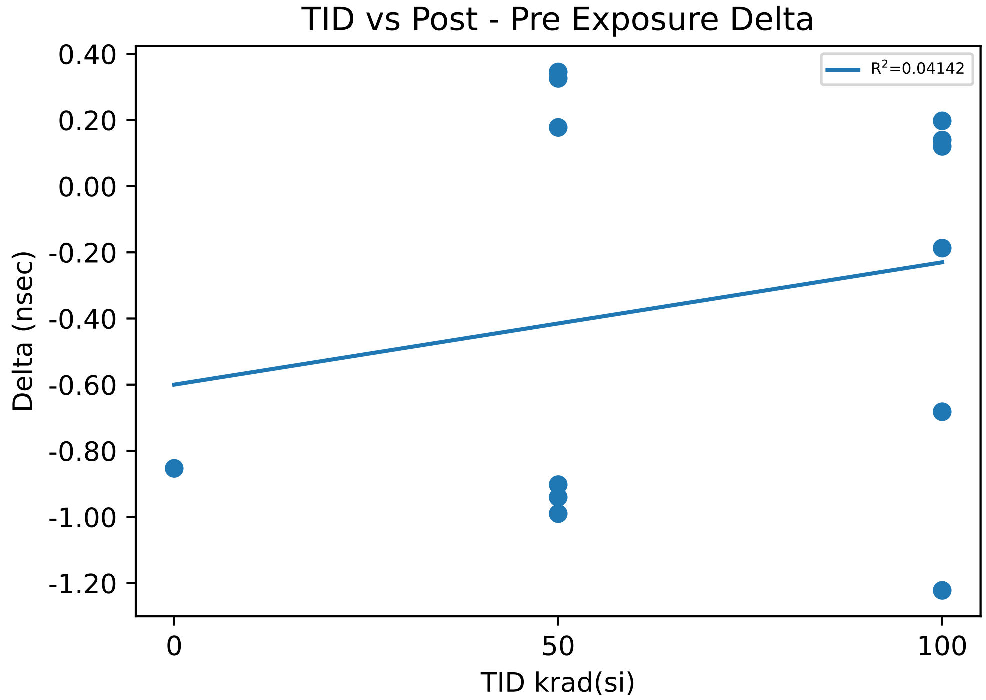
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	25.213	26.008	0.7944
60	50	Biased	26.023	24.968	-1.055
61	50	Biased	25.224	26.033	0.8096
63	100	Biased	25.246	25.916	0.6699
64	100	Biased	26.262	26.08	-0.1826
65	100	Biased	25.359	24.939	-0.4199
66	50	Unbiased	26.223	25.211	-1.012
67	50	Unbiased	25.466	26.25	0.7841
68	50	Unbiased	26.042	24.99	-1.0524
69	100	Unbiased	25.35	25.876	0.5261
70	100	Unbiased	26.316	25.02	-1.2959
71	100	Unbiased	25.694	26.323	0.6292
72	0	Control	26.322	25.451	-0.8705

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.322	26.322	26.322		25.451	25.451	25.451		-0.8705	-0.8705	-0.8705	
50	25.213	25.698	26.223	0.4502	24.968	25.577	26.25	0.58241	-1.055	-0.12188	0.8096	1.0057
100	25.246	25.705	26.316	0.47752	24.939	25.692	26.323	0.57456	-1.2959	-0.0122	0.6699	0.77583

Device Test: 111.4 Prop Delay HO On IIM Interlock VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

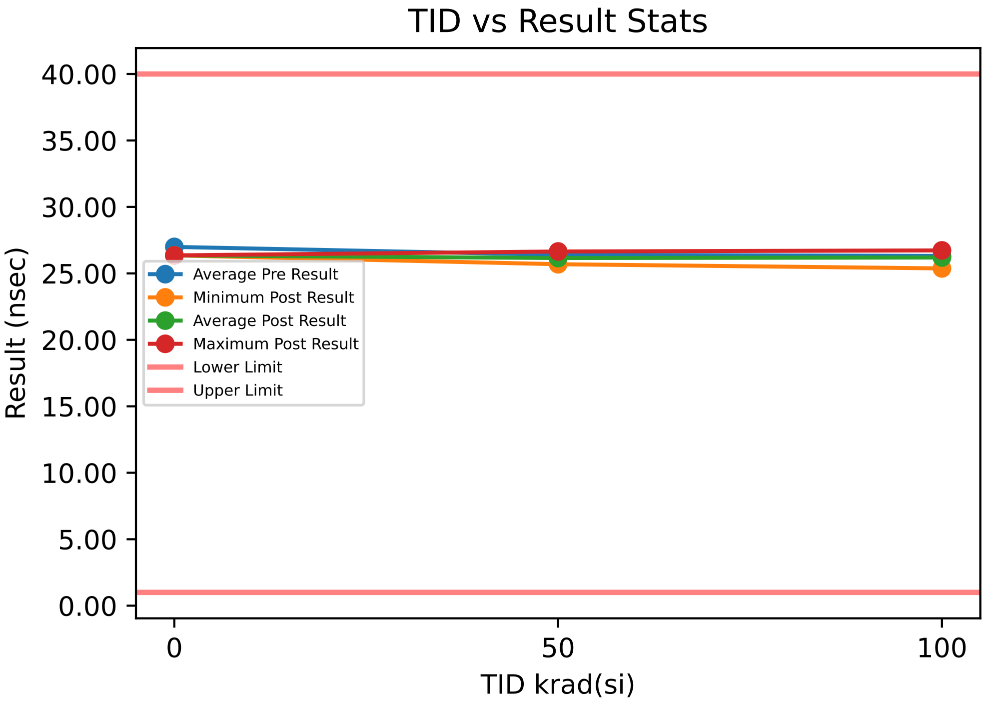
Test Results (Lower Limit = 1.0, Upper Limit = 40.0 (nsec))

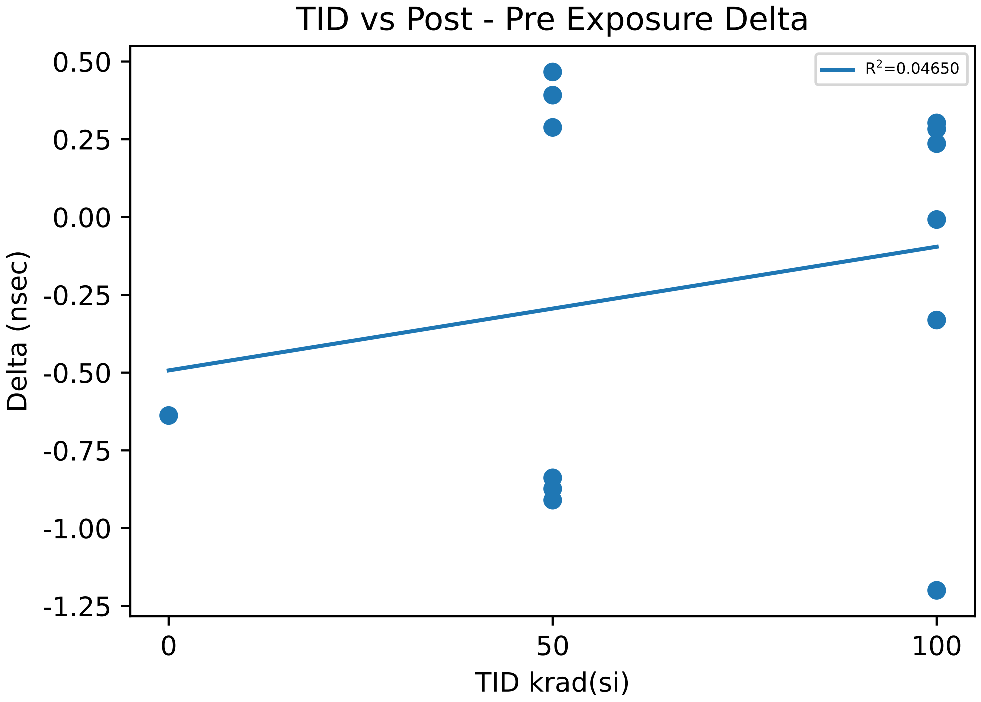
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	25.257	25.583	0.326
60	50	Biased	25.639	24.649	-0.99
61	50	Biased	25.398	25.576	0.1777
63	100	Biased	25.067	25.207	0.1396
64	100	Biased	25.584	25.397	-0.1871
65	100	Biased	24.89	24.208	-0.6819
66	50	Unbiased	25.663	24.723	-0.9403
67	50	Unbiased	25.042	25.387	0.3454
68	50	Unbiased	25.624	24.722	-0.9023
69	100	Unbiased	25.032	25.152	0.1205
70	100	Unbiased	25.5	24.278	-1.2219
71	100	Unbiased	25.045	25.243	0.1975
72	0	Control	25.516	24.663	-0.8531

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.516	25.516	25.516		24.663	24.663	24.663		-0.8531	-0.8531	-0.8531	
50	25.042	25.437	25.663	0.2519	24.649	25.107	25.583	0.45395	-0.99	-0.33058	0.3454	0.67526
100	24.89	25.186	25.584	0.28391	24.208	24.914	25.397	0.52662	-1.2219	-0.27222	0.1975	0.56946

Device Test: 111.5 Prop Delay HO Off IIM Interlock VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

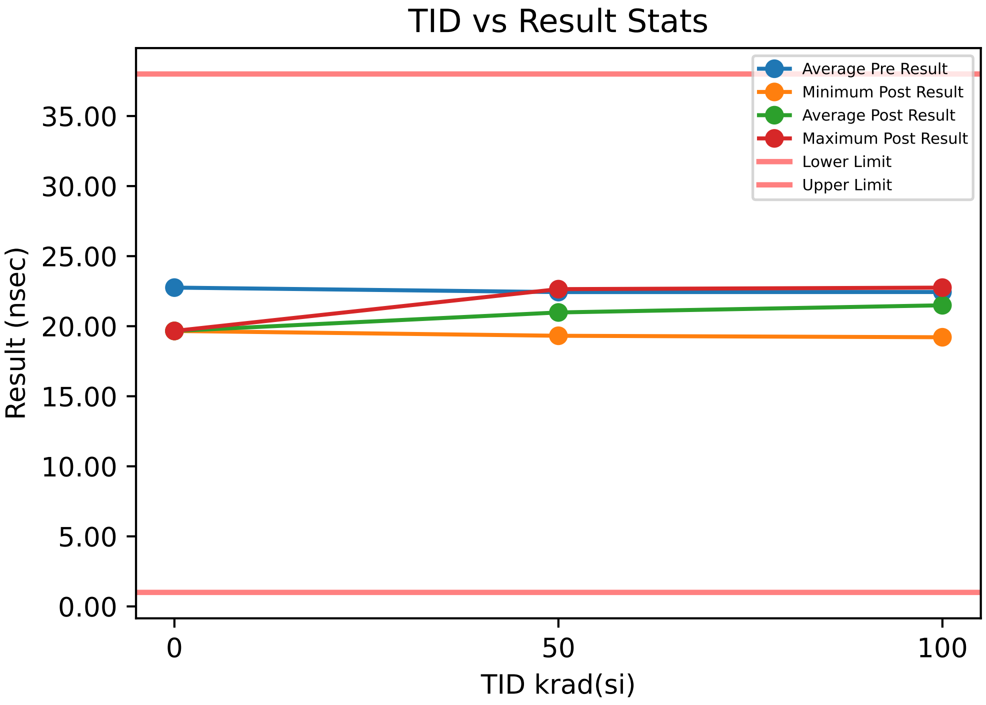
Test Results (Lower Limit = 1.0, Upper Limit = 40.0 (nsec))

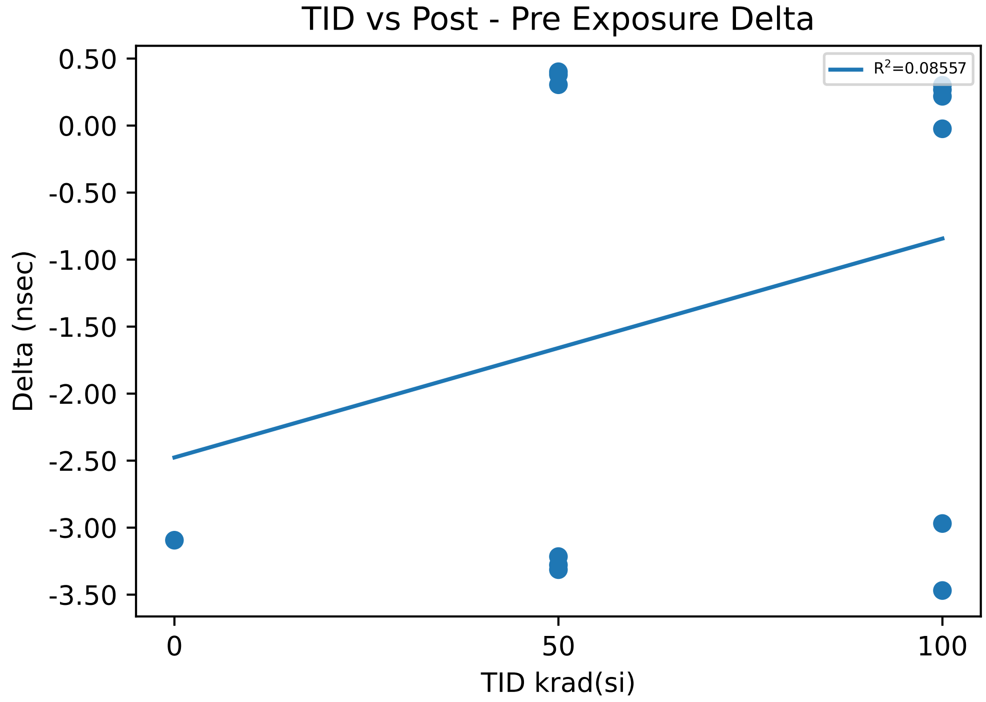
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	26.099	26.565	0.4665
60	50	Biased	26.72	25.81	-0.91
61	50	Biased	26.256	26.648	0.3919
63	100	Biased	26.294	26.53	0.2361
64	100	Biased	26.737	26.73	-0.0079
65	100	Biased	26.213	25.882	-0.331
66	50	Unbiased	26.527	25.689	-0.8382
67	50	Unbiased	26.219	26.507	0.2882
68	50	Unbiased	26.577	25.703	-0.8734
69	100	Unbiased	25.935	26.237	0.3027
70	100	Unbiased	26.574	25.375	-1.1999
71	100	Unbiased	26.127	26.41	0.283
72	0	Control	26.992	26.354	-0.6379

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.992	26.992	26.992		26.354	26.354	26.354		-0.6379	-0.6379	-0.6379	
50	26.099	26.399	26.72	0.24251	25.689	26.154	26.648	0.46374	-0.91	-0.24583	0.4665	0.69068
100	25.935	26.313	26.737	0.29543	25.375	26.194	26.73	0.49344	-1.1999	-0.1195	0.3027	0.58158

Device Test: 111.6 Prop Delay LO On IIM Interlock Disable VIN_12V





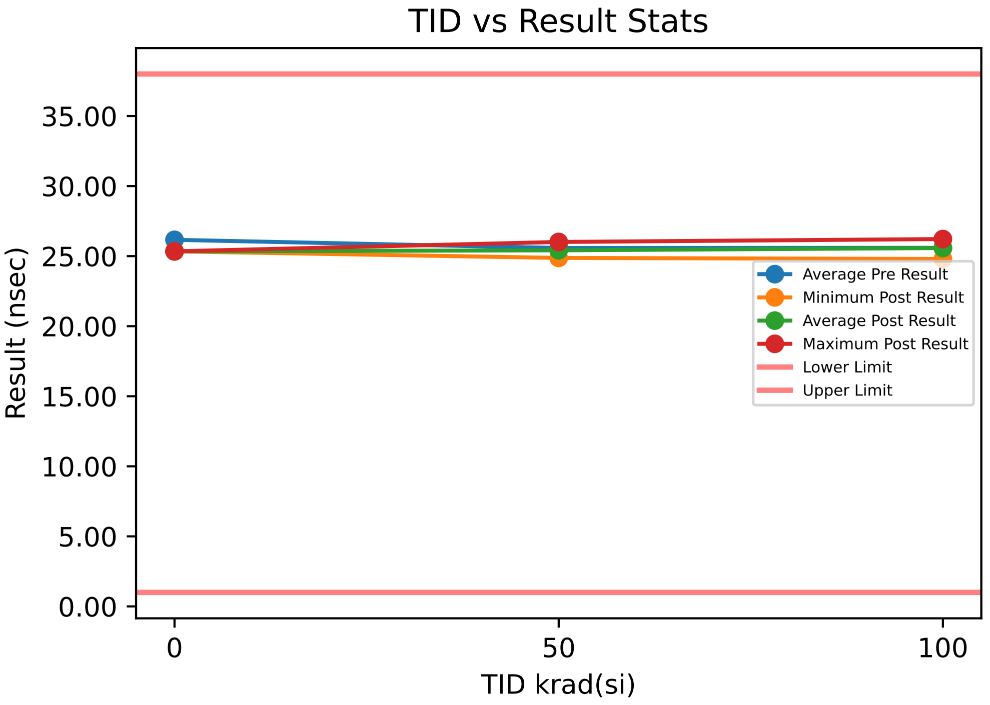
Test Results (Lower Limit = 1.0, Upper Limit = 38.0 (nsec))

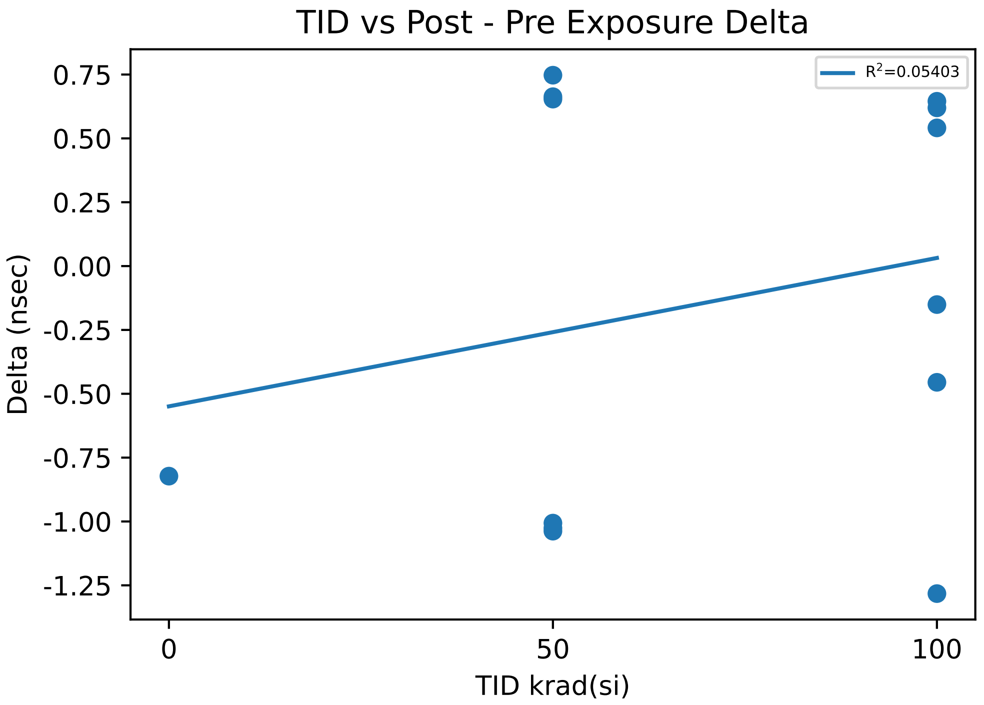
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	22.172	22.574	0.4016
60	50	Biased	22.67	19.391	-3.2787
61	50	Biased	22.075	22.454	0.3793
63	100	Biased	22.195	22.496	0.3007
64	100	Biased	22.741	22.718	-0.024
65	100	Biased	22.18	19.211	-2.9692
66	50	Unbiased	22.718	19.502	-3.2159
67	50	Unbiased	22.34	22.645	0.3046
68	50	Unbiased	22.63	19.316	-3.3136
69	100	Unbiased	22.284	22.503	0.2184
70	100	Unbiased	22.743	19.274	-3.4691
71	100	Unbiased	22.485	22.753	0.2676
72	0	Control	22.754	19.66	-3.0938

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.754	22.754	22.754		19.66	19.66	19.66		-3.0938	-3.0938	-3.0938	
50	22.075	22.434	22.718	0.27596	19.316	20.98	22.645	1.7299	-3.3136	-1.4538	0.4016	1.9894
100	22.18	22.438	22.743	0.25948	19.211	21.492	22.753	1.7462	-3.4691	-0.94593	0.3007	1.7716

Device Test: 111.7 Prop Delay LO Off IIM Interlock Disable VIN_12V





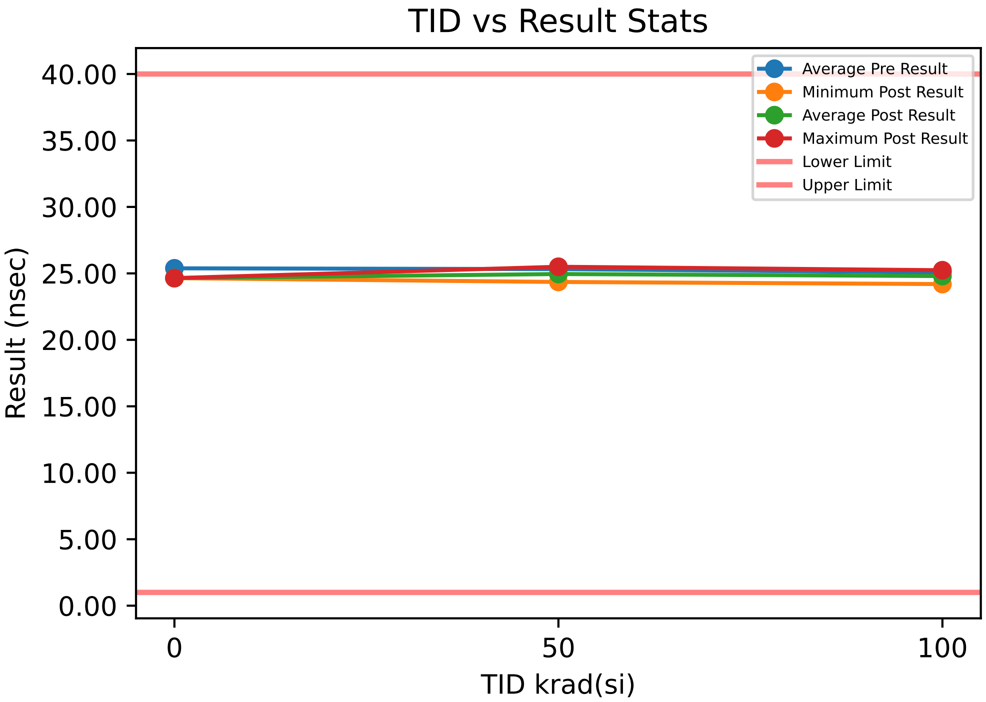
Test Results (Lower Limit = 1.0, Upper Limit = 38.0 (nsec))

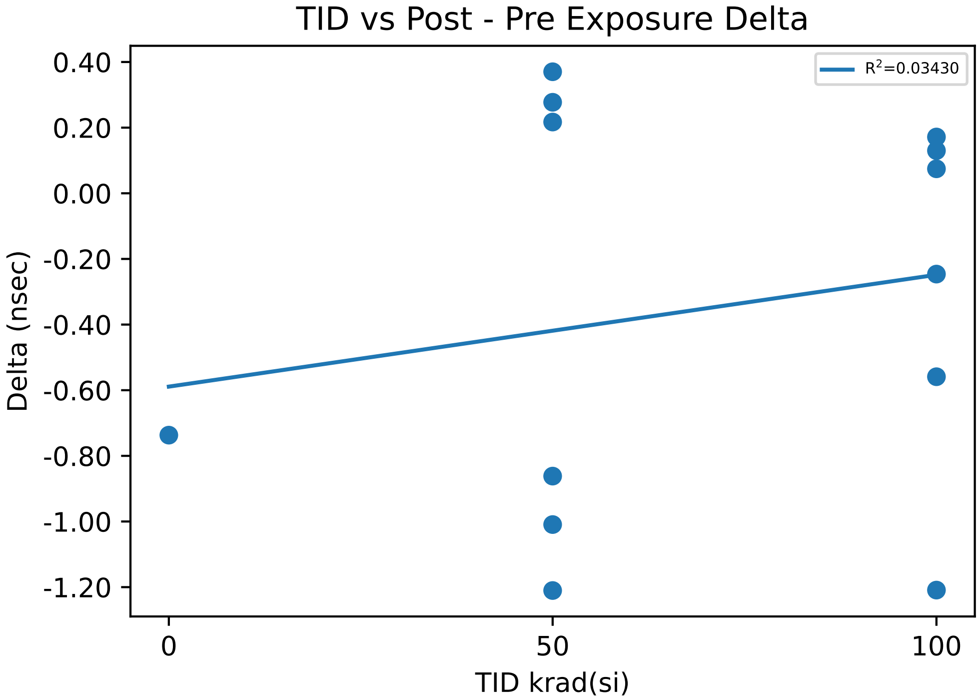
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	25.077	25.731	0.6538
60	50	Biased	25.919	24.913	-1.0064
61	50	Biased	25.141	25.888	0.7474
63	100	Biased	25.158	25.804	0.6453
64	100	Biased	26.108	25.957	-0.1507
65	100	Biased	25.251	24.796	-0.4551
66	50	Unbiased	26.118	25.08	-1.0379
67	50	Unbiased	25.349	26.012	0.6632
68	50	Unbiased	25.898	24.873	-1.0257
69	100	Unbiased	25.241	25.782	0.5411
70	100	Unbiased	26.195	24.912	-1.2824
71	100	Unbiased	25.6	26.219	0.6196
72	0	Control	26.165	25.342	-0.8225

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.165	26.165	26.165		25.342	25.342	25.342		-0.8225	-0.8225	-0.8225	
50	25.077	25.584	26.118	0.44831	24.873	25.416	26.012	0.51744	-1.0379	-0.1676	0.7474	0.93803
100	25.158	25.592	26.195	0.45978	24.796	25.578	26.219	0.58345	-1.2824	-0.0137	0.6453	0.77024

Device Test: 111.8 Prop Delay HO On IIM Interlock Disable VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

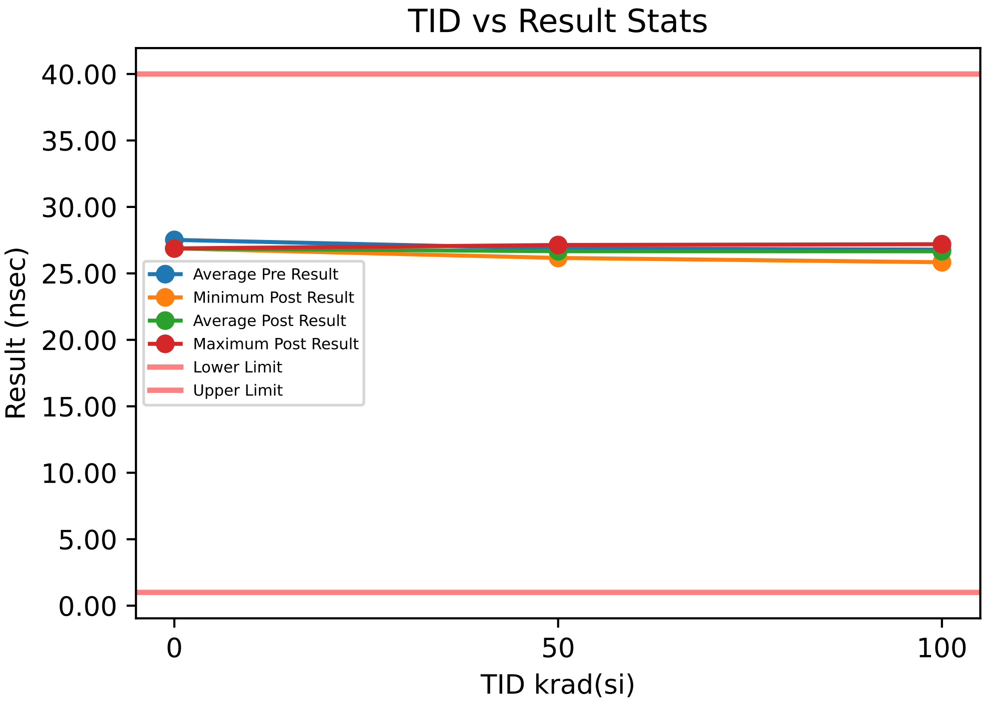
Test Results (Lower Limit = 1.0, Upper Limit = 40.0 (nsec))

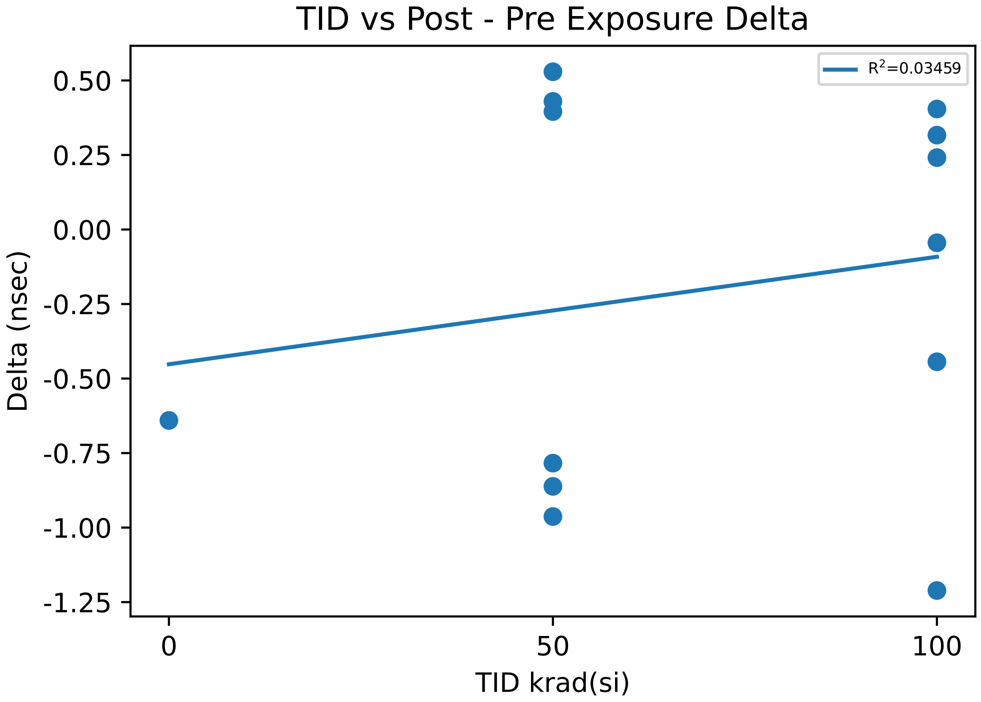
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	25.127	25.497	0.3703
60	50	Biased	25.566	24.355	-1.2103
61	50	Biased	25.274	25.492	0.2171
63	100	Biased	24.951	25.081	0.13
64	100	Biased	25.483	25.237	-0.2462
65	100	Biased	24.784	24.225	-0.5589
66	50	Unbiased	25.543	24.682	-0.8617
67	50	Unbiased	24.91	25.187	0.2773
68	50	Unbiased	25.506	24.497	-1.0093
69	100	Unbiased	24.91	24.984	0.0746
70	100	Unbiased	25.405	24.196	-1.209
71	100	Unbiased	24.896	25.067	0.1715
72	0	Control	25.381	24.645	-0.7369

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.381	25.381	25.381		24.645	24.645	24.645		-0.7369	-0.7369	-0.7369	
50	24.91	25.321	25.566	0.26561	24.355	24.952	25.497	0.50591	-1.2103	-0.36943	0.3703	0.73052
100	24.784	25.071	25.483	0.29486	24.196	24.798	25.237	0.46273	-1.209	-0.273	0.1715	0.53654

Device Test: 111.9 Prop Delay HO Off IIM Interlock Disable VIN_12V





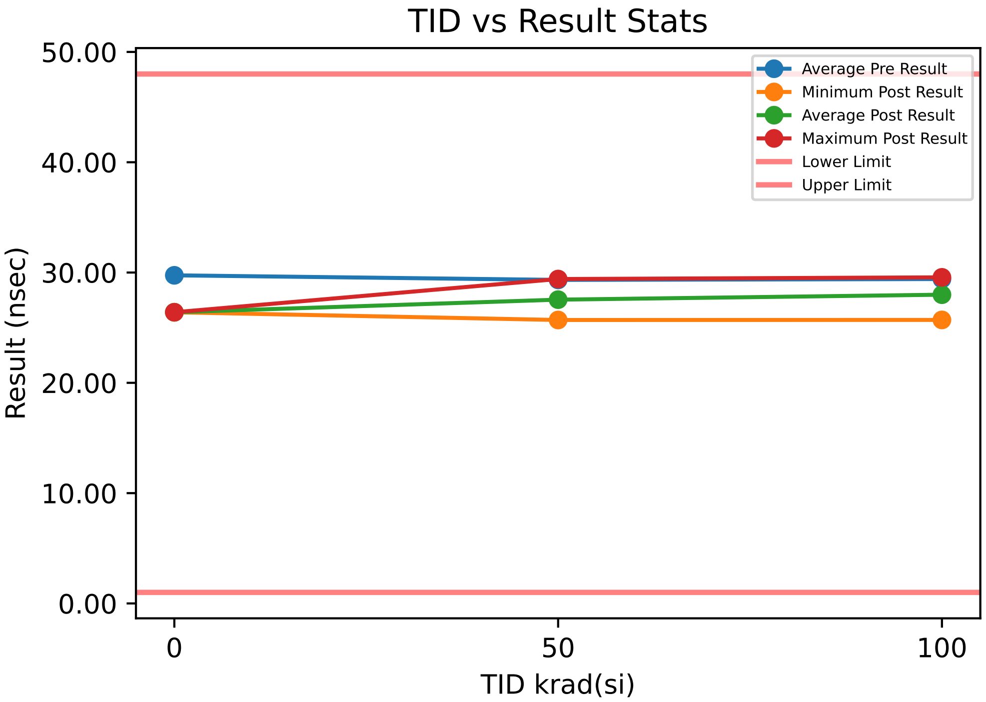
Test Results (Lower Limit = 1.0, Upper Limit = 40.0 (nsec))

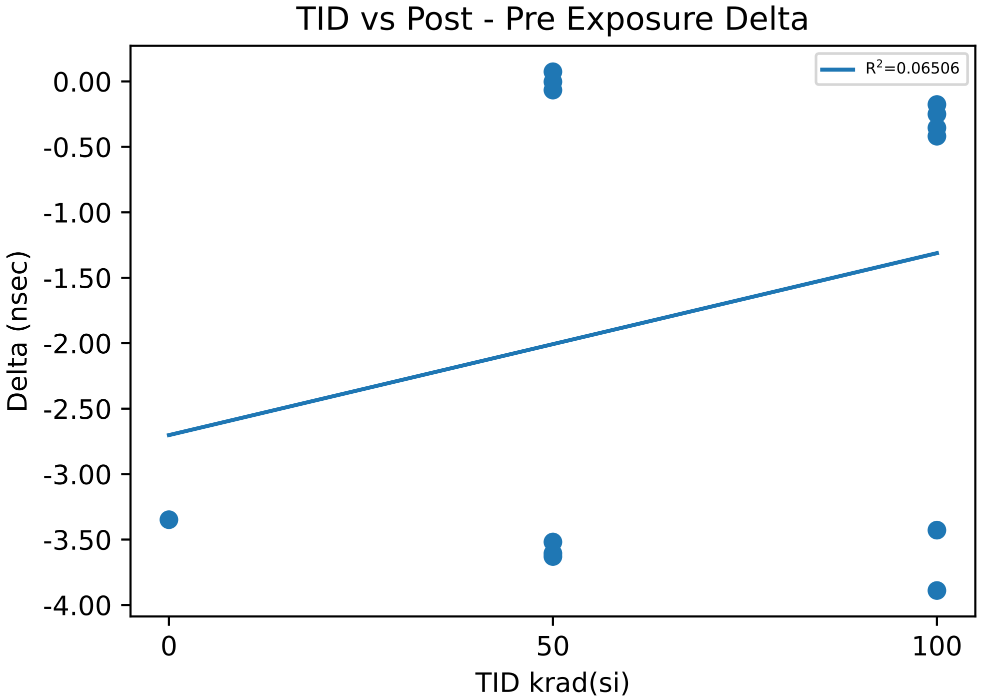
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	26.595	27.124	0.5292
60	50	Biased	27.209	26.247	-0.9628
61	50	Biased	26.694	27.09	0.3956
63	100	Biased	26.779	27.021	0.2411
64	100	Biased	27.239	27.194	-0.0445
65	100	Biased	26.669	26.226	-0.4437
66	50	Unbiased	27.025	26.163	-0.8618
67	50	Unbiased	26.705	27.135	0.4298
68	50	Unbiased	27.022	26.238	-0.7838
69	100	Unbiased	26.381	26.697	0.3166
70	100	Unbiased	27.049	25.838	-1.2111
71	100	Unbiased	26.596	27	0.4042
72	0	Control	27.52	26.879	-0.6405

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	27.52	27.52	27.52		26.879	26.879	26.879		-0.6405	-0.6405	-0.6405	
50	26.595	26.875	27.209	0.24321	26.163	26.666	27.135	0.49423	-0.9628	-0.20897	0.5292	0.72709
100	26.381	26.786	27.239	0.31249	25.838	26.663	27.194	0.52868	-1.2111	-0.1229	0.4042	0.61591

Device Test: 112.0 Prop Delay LO Off PWM VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

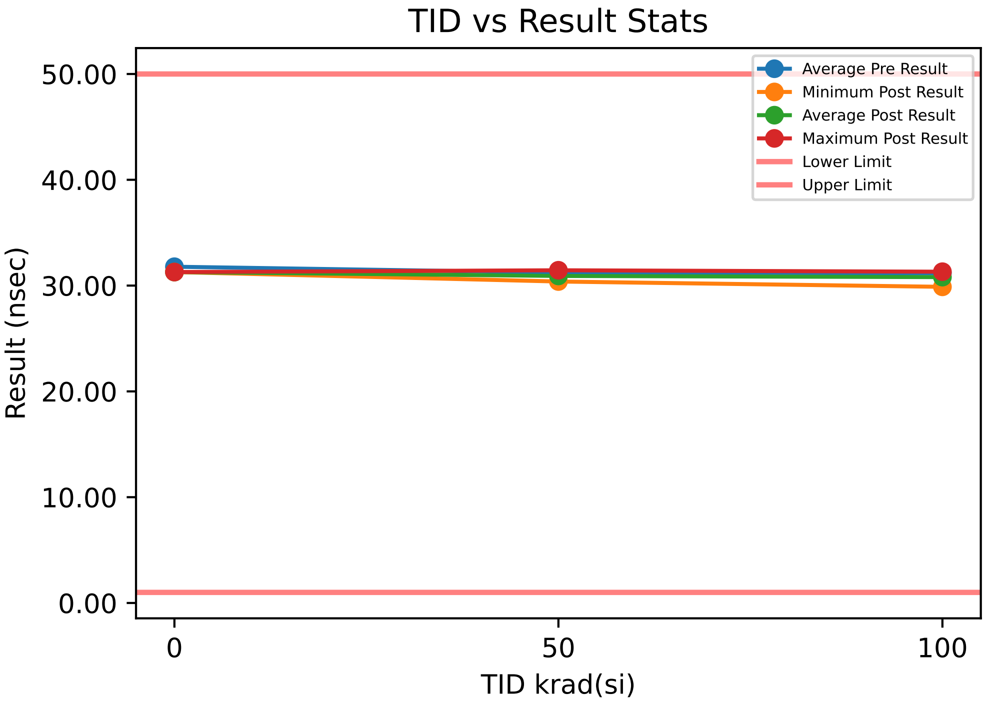
Test Results (Lower Limit = 1.0, Upper Limit = 48.0 (nsec))

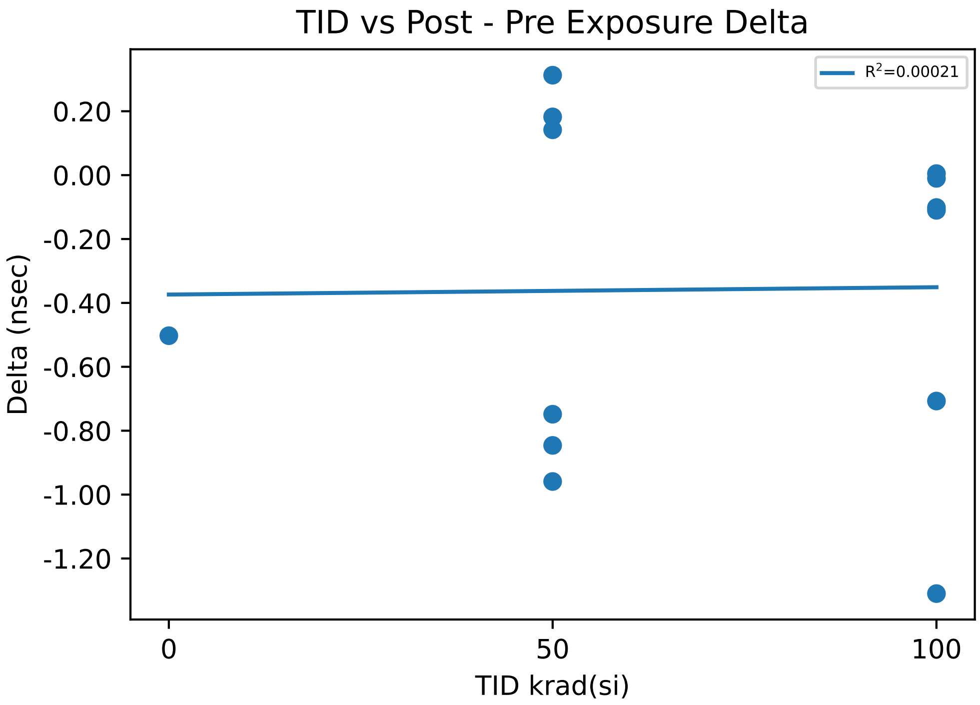
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	29.061	29.059	-0.0028
60	50	Biased	29.391	25.785	-3.6059
61	50	Biased	29.192	29.266	0.0738
63	100	Biased	29.048	28.871	-0.1764
64	100	Biased	29.59	29.171	-0.4187
65	100	Biased	29.144	25.716	-3.4281
66	50	Unbiased	29.545	26.026	-3.5186
67	50	Unbiased	29.477	29.411	-0.0664
68	50	Unbiased	29.327	25.698	-3.6296
69	100	Unbiased	29.272	28.918	-0.3547
70	100	Unbiased	29.593	25.704	-3.8892
71	100	Unbiased	29.814	29.564	-0.2502
72	0	Control	29.747	26.399	-3.3483

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	29.747	29.747	29.747		26.399	26.399	26.399		-3.3483	-3.3483	-3.3483	
50	29.061	29.332	29.545	0.18043	25.698	27.541	29.411	1.8736	-3.6296	-1.7916	0.0738	1.9651
100	29.048	29.41	29.814	0.30003	25.704	27.991	29.564	1.7836	-3.8892	-1.4195	-0.1764	1.7425

Device Test: 112.1 Prop Delay HO Off PWM VIN_14V





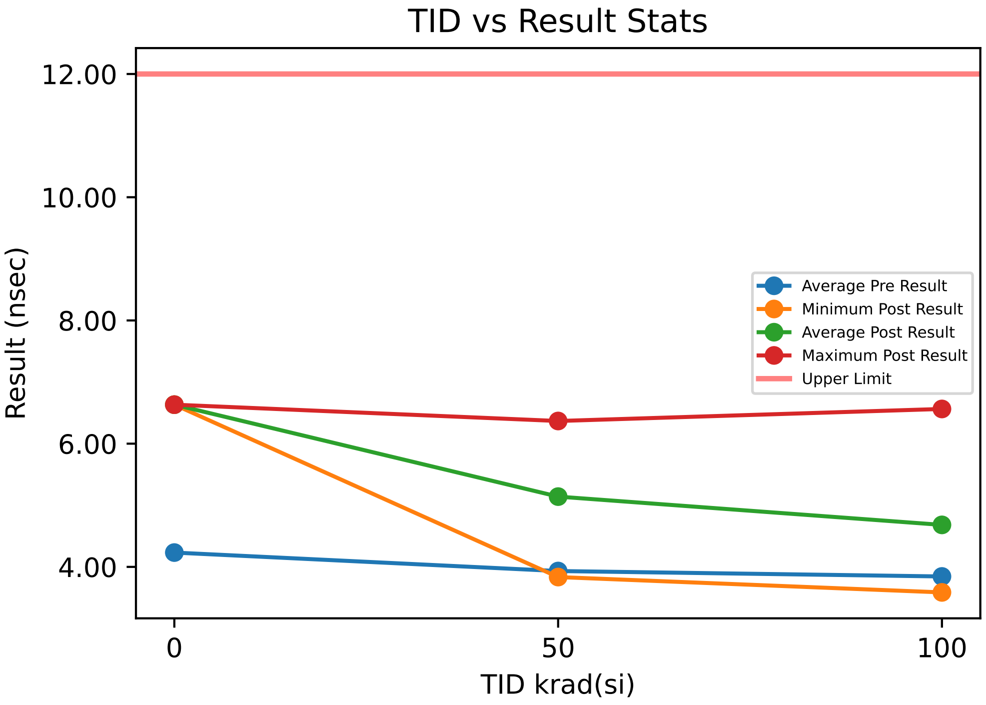
Test Results (Lower Limit = 1.0, Upper Limit = 50.0 (nsec))

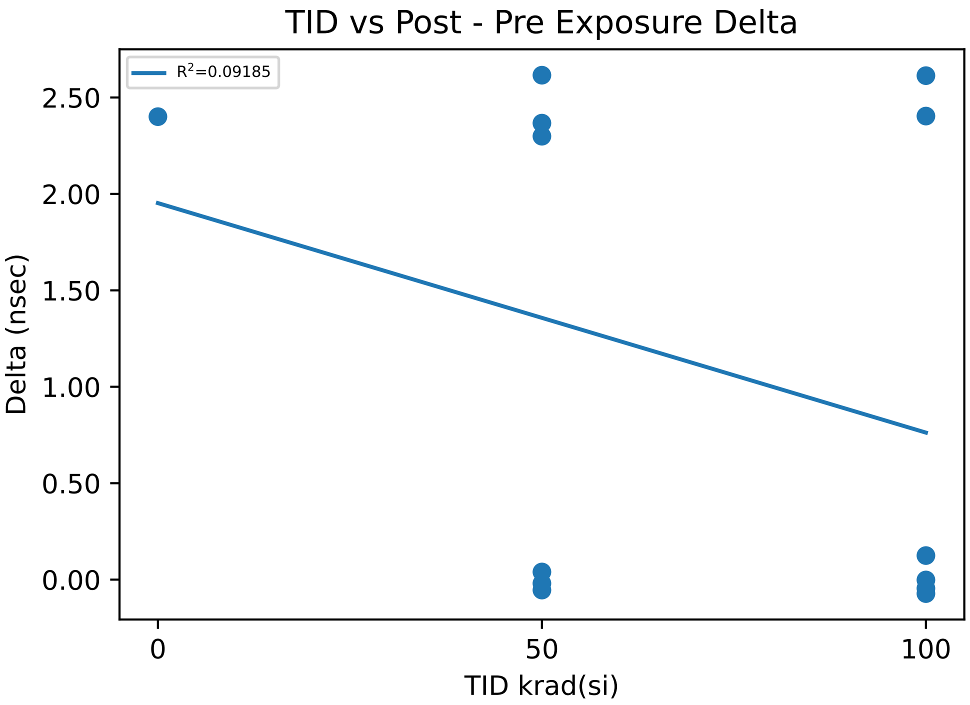
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	31.022	31.335	0.3128
60	50	Biased	31.409	30.45	-0.959
61	50	Biased	31.257	31.439	0.1823
63	100	Biased	31.144	31.034	-0.1102
64	100	Biased	31.39	31.288	-0.1014
65	100	Biased	31.093	30.386	-0.7071
66	50	Unbiased	31.161	30.413	-0.7484
67	50	Unbiased	31.306	31.448	0.1419
68	50	Unbiased	31.231	30.385	-0.846
69	100	Unbiased	30.893	30.897	0.0048
70	100	Unbiased	31.193	29.883	-1.3099
71	100	Unbiased	31.322	31.312	-0.0101
72	0	Control	31.783	31.281	-0.5026

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.783	31.783	31.783		31.281	31.281	31.281		-0.5026	-0.5026	-0.5026	
50	31.022	31.231	31.409	0.13162	30.385	30.912	31.448	0.545	-0.959	-0.3194	0.3128	0.589
100	30.893	31.172	31.39	0.1763	29.883	30.8	31.312	0.56151	-1.3099	-0.37232	0.0048	0.53041

Device Test: 112.10 Delay Match LO On HO Off IIM Interlock VIN_14V





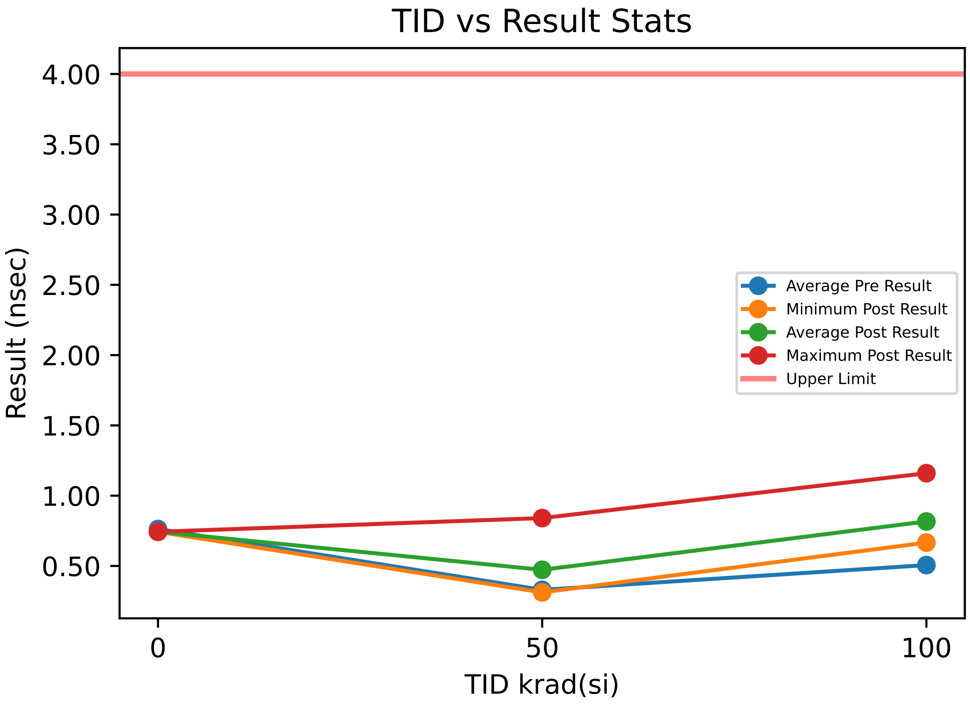
Test Results (Upper Limit = 12.0 (nsec))

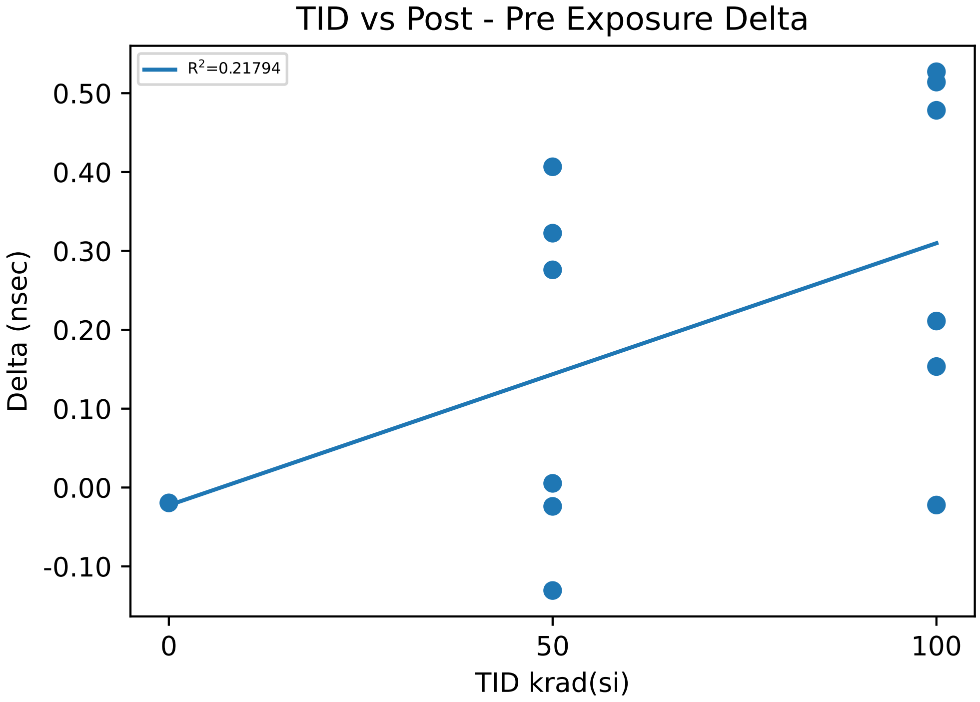
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.9042	3.9439	0.0397
60	50	Biased	4.0182	6.3174	2.2992
61	50	Biased	4.129	4.0749	-0.0541
63	100	Biased	4.0708	3.9984	-0.0724
64	100	Biased	3.9765	4.1013	0.1248
65	100	Biased	3.9502	6.5634	2.6132
66	50	Unbiased	3.7524	6.368	2.6156
67	50	Unbiased	3.8545	3.8349	-0.0196
68	50	Unbiased	3.9382	6.3052	2.367
69	100	Unbiased	3.6314	3.586	-0.0454
70	100	Unbiased	3.7747	6.1783	2.4036
71	100	Unbiased	3.6652	3.6635	-0.0017
72	0	Control	4.2324	6.633	2.4006

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.2324	4.2324	4.2324		6.633	6.633	6.633		2.4006	2.4006	2.4006	
50	3.7524	3.9327	4.129	0.13062	3.8349	5.1407	6.368	1.3054	-0.0541	1.208	2.6156	1.3402
100	3.6314	3.8448	4.0708	0.18013	3.586	4.6818	6.5634	1.3283	-0.0724	0.83702	2.6132	1.2981

Device Test: 112.11 Delay Match LO Off HO On IIM Interlock VIN_14V





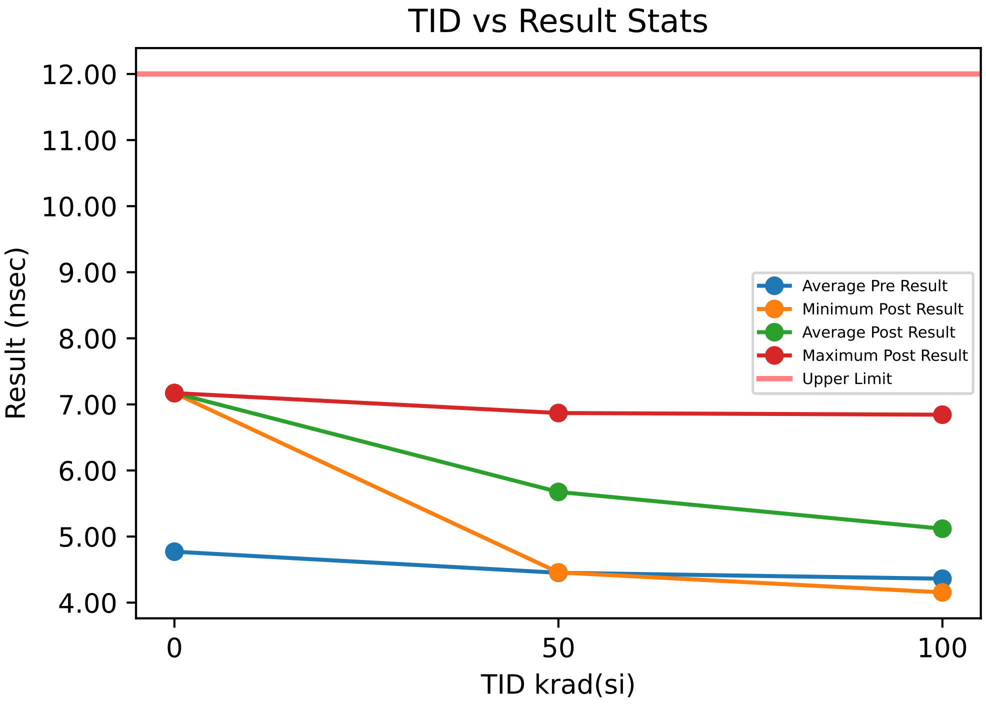
Test Results (Upper Limit = 4.0 (nsec))

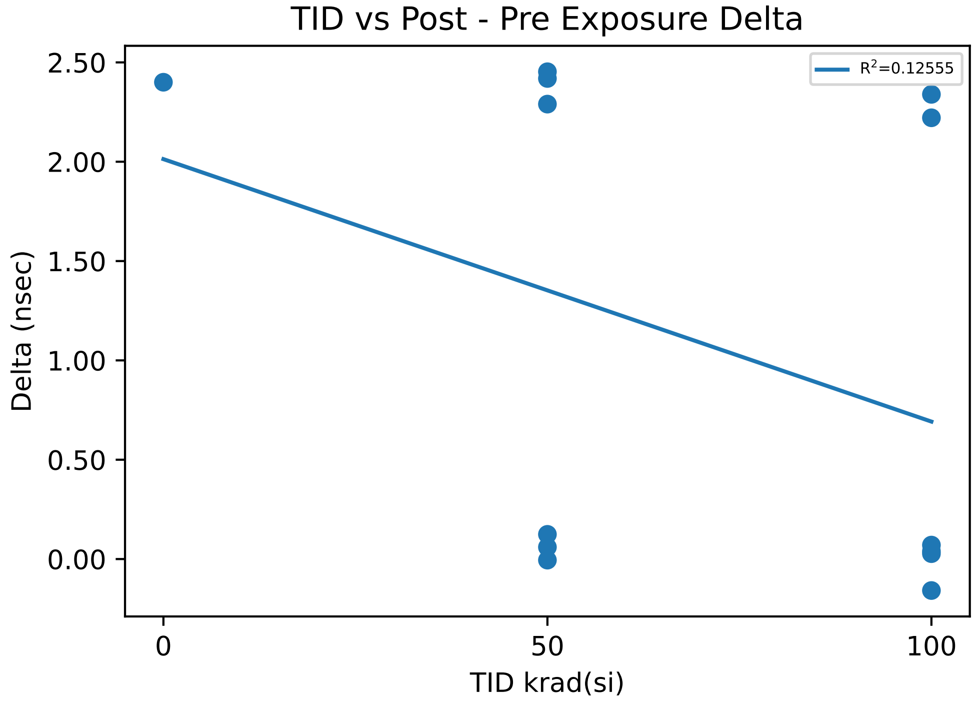
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0765	0.399	0.3225
60	50	Biased	0.3433	0.3486	0.0053
61	50	Biased	0.1186	0.3946	0.276
63	100	Biased	0.1923	0.7195	0.5272
64	100	Biased	0.6067	0.7601	0.1534
65	100	Biased	0.455	0.6661	0.2111
66	50	Unbiased	0.5646	0.5407	-0.0239
67	50	Unbiased	0.434	0.8407	0.4067
68	50	Unbiased	0.4425	0.3119	-0.1306
69	100	Unbiased	0.3278	0.8061	0.4783
70	100	Unbiased	0.8093	0.7871	-0.0222
71	100	Unbiased	0.6458	1.1599	0.5141
72	0	Control	0.7627	0.7432	-0.0195

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.7627	0.7627	0.7627		0.7432	0.7432	0.7432		-0.0195	-0.0195	-0.0195	
50	0.0765	0.32992	0.5646	0.19372	0.3119	0.47258	0.8407	0.19639	-0.1306	0.14267	0.4067	0.2196
100	0.1923	0.50615	0.8093	0.22558	0.6661	0.81647	1.1599	0.17556	-0.0222	0.31032	0.5272	0.22883

Device Test: 112.12 Delay Match LO On HO Off IIM Interlock Disable VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

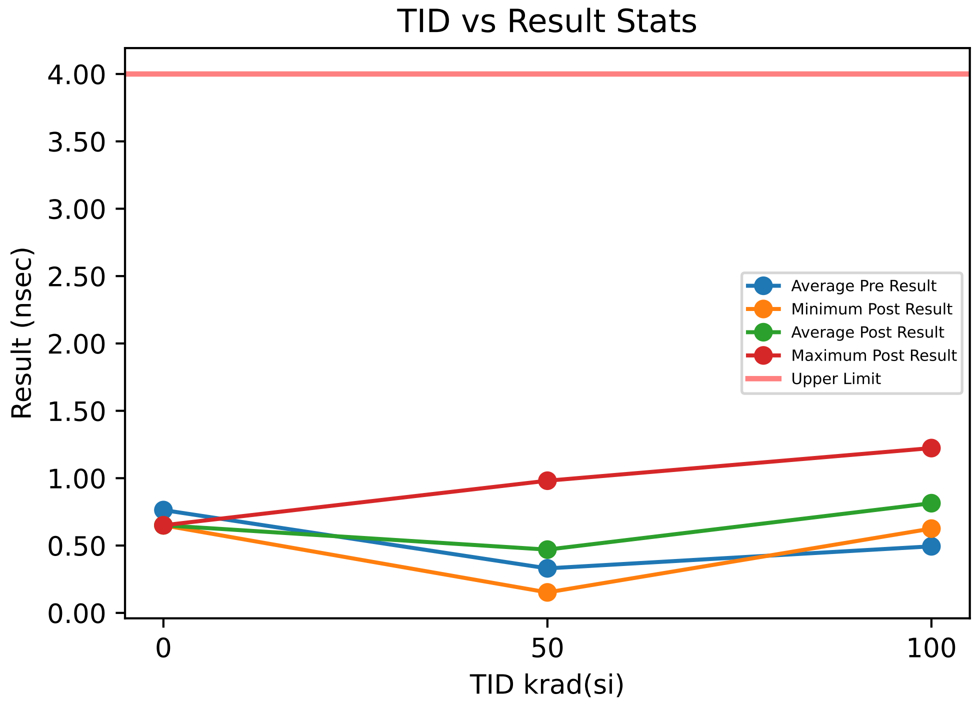
Test Results (Upper Limit = 12.0 (nsec))

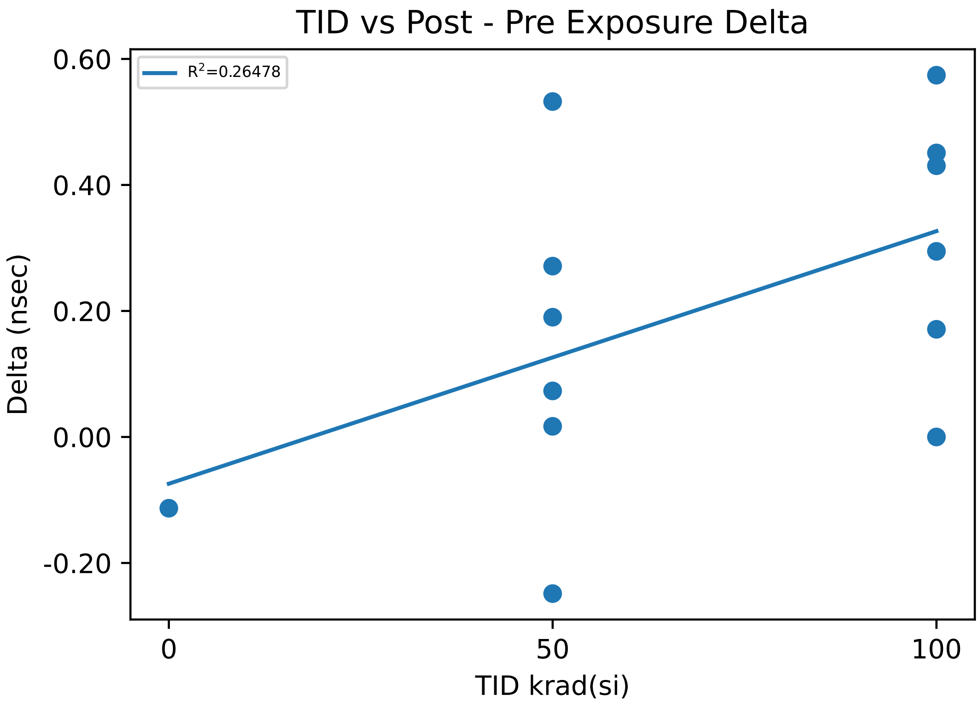
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.4111	4.5354	0.1243
60	50	Biased	4.516	6.806	2.29
61	50	Biased	4.6261	4.6207	-0.0054
63	100	Biased	4.5967	4.4383	-0.1584
64	100	Biased	4.4832	4.5224	0.0392
65	100	Biased	4.5048	6.8439	2.3391
66	50	Unbiased	4.3089	6.7618	2.4529
67	50	Unbiased	4.3973	4.4573	0.06
68	50	Unbiased	4.4504	6.8695	2.4191
69	100	Unbiased	4.1276	4.1548	0.0272
70	100	Unbiased	4.3075	6.5287	2.2212
71	100	Unbiased	4.1524	4.2227	0.0703
72	0	Control	4.7712	7.1713	2.4001

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.7712	4.7712	4.7712		7.1713	7.1713	7.1713		2.4001	2.4001	2.4001	
50	4.3089	4.4516	4.6261	0.10913	4.4573	5.6751	6.8695	1.2474	-0.0054	1.2235	2.4529	1.2768
100	4.1276	4.362	4.5967	0.19596	4.1548	5.1185	6.8439	1.226	-0.1584	0.75643	2.3391	1.1836

Device Test: 112.13 Delay Match LO Off HO On IIM Interlock Disable VIN_14V





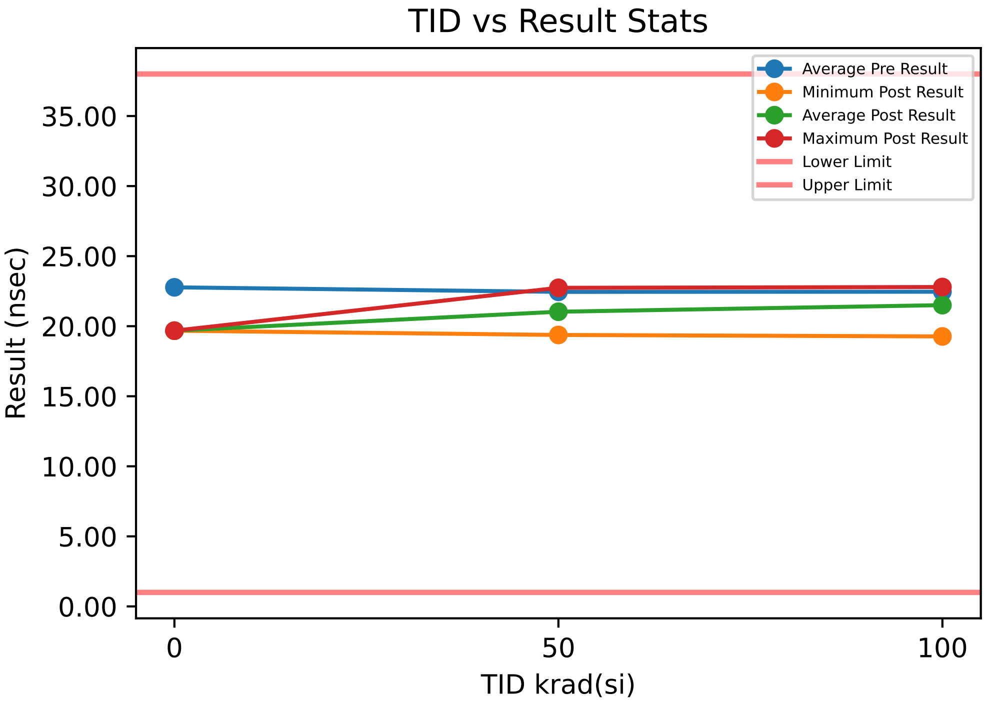
Test Results (Upper Limit = 4.0 (nsec))

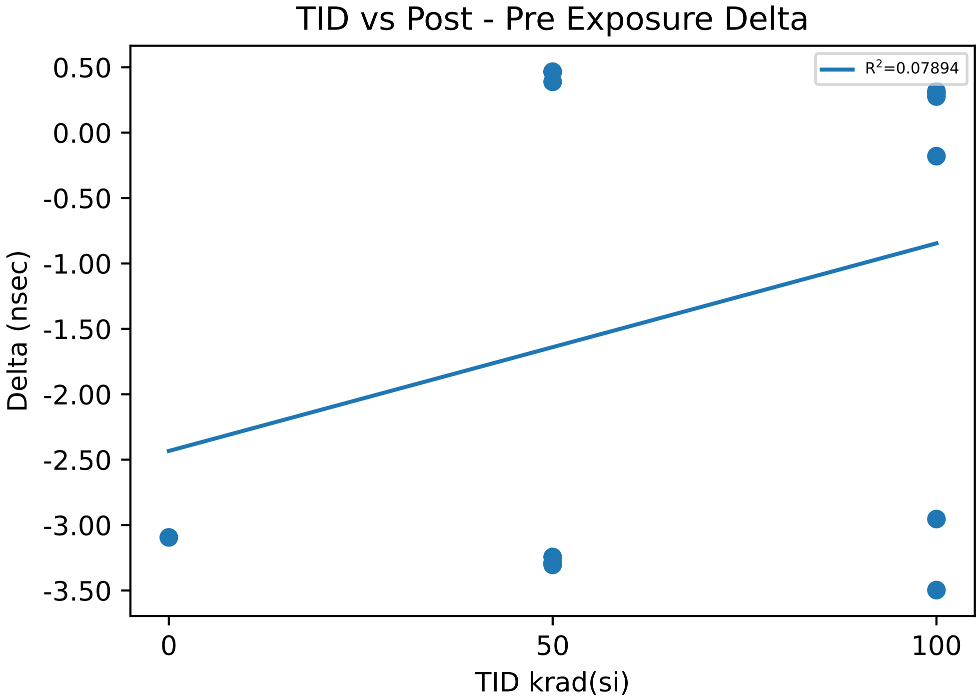
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0667	0.3379	0.2712
60	50	Biased	0.3633	0.3802	0.0169
61	50	Biased	0.1477	0.3378	0.1901
63	100	Biased	0.1951	0.6256	0.4305
64	100	Biased	0.6059	0.7768	0.1709
65	100	Biased	0.4256	0.7202	0.2946
66	50	Unbiased	0.5562	0.6293	0.0731
67	50	Unbiased	0.4488	0.9812	0.5324
68	50	Unbiased	0.4008	0.1522	-0.2486
69	100	Unbiased	0.3116	0.7624	0.4508
70	100	Unbiased	0.7773	0.7773	0
71	100	Unbiased	0.6492	1.2234	0.5742
72	0	Control	0.7634	0.6503	-0.1131

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.7634	0.7634	0.7634		0.6503	0.6503	0.6503		-0.1131	-0.1131	-0.1131	
50	0.0667	0.33058	0.5562	0.18653	0.1522	0.46977	0.9812	0.29349	-0.2486	0.13918	0.5324	0.26243
100	0.1951	0.49412	0.7773	0.22098	0.6256	0.81428	1.2234	0.20847	0	0.32017	0.5742	0.20939

Device Test: 112.2 Prop Delay LO On IIM Interlock VIN_14V





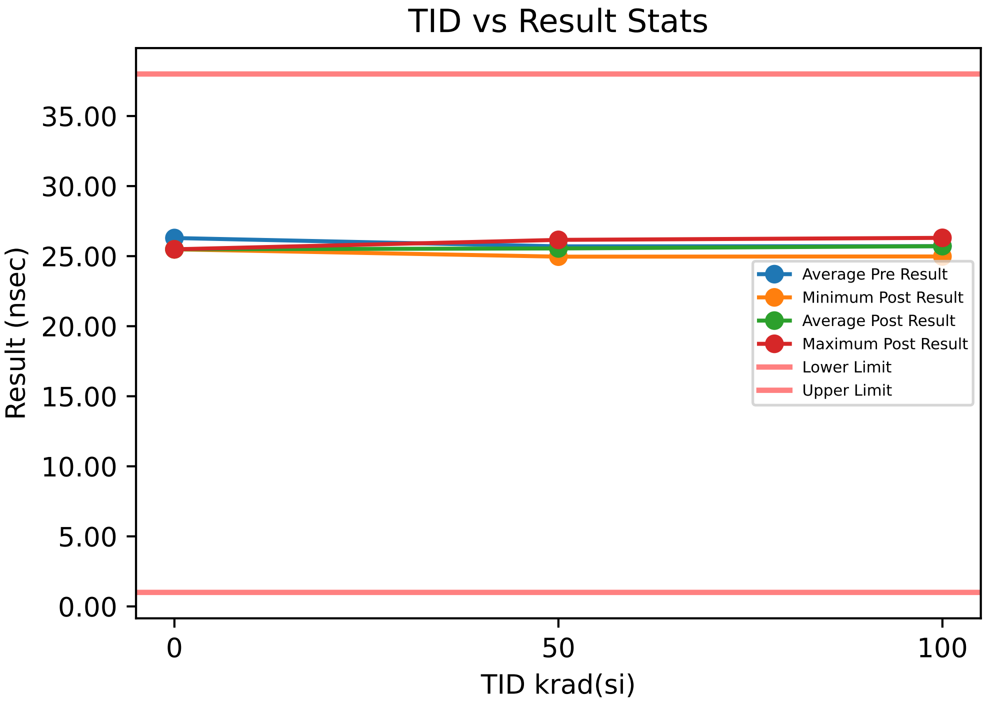
Test Results (Lower Limit = 1.0, Upper Limit = 38.0 (nsec))

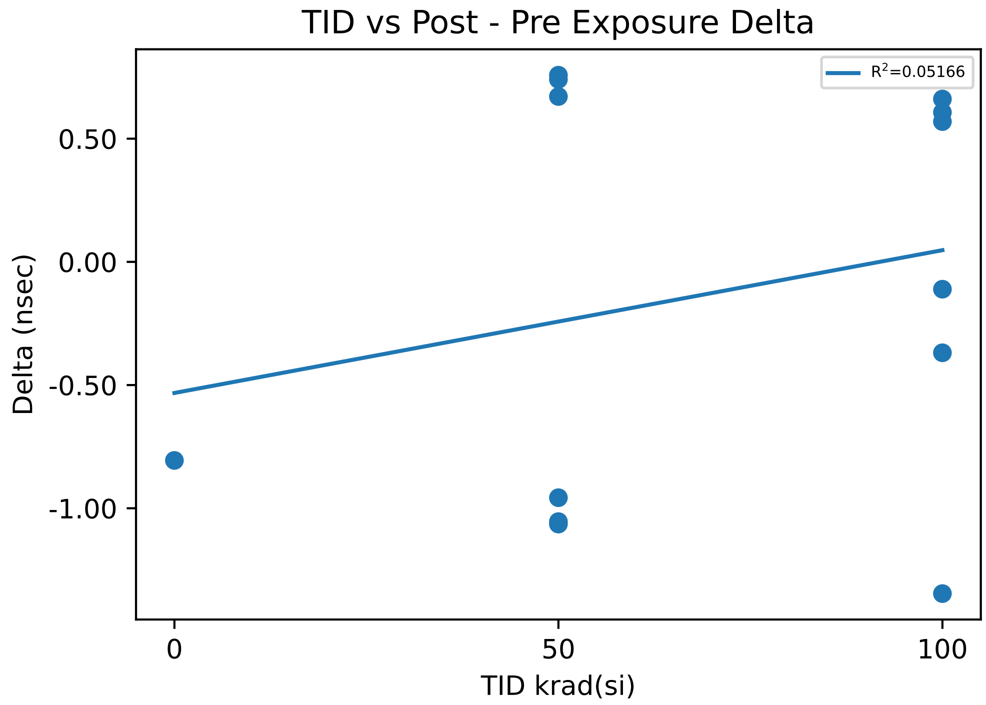
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	22.181	22.647	0.466
60	50	Biased	22.682	19.395	-3.2877
61	50	Biased	22.108	22.573	0.4648
63	100	Biased	22.206	22.483	0.276
64	100	Biased	22.771	22.591	-0.1797
65	100	Biased	22.232	19.279	-2.9538
66	50	Unbiased	22.769	19.465	-3.3043
67	50	Unbiased	22.35	22.739	0.3886
68	50	Unbiased	22.619	19.375	-3.244
69	100	Unbiased	22.301	22.602	0.3008
70	100	Unbiased	22.767	19.27	-3.4971
71	100	Unbiased	22.479	22.796	0.3168
72	0	Control	22.773	19.679	-3.0943

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.773	22.773	22.773		19.679	19.679	19.679		-3.0943	-3.0943	-3.0943	
50	22.108	22.452	22.769	0.27684	19.375	21.032	22.739	1.7765	-3.3043	-1.4194	0.466	2.037
100	22.206	22.459	22.771	0.25781	19.27	21.503	22.796	1.7296	-3.4971	-0.95617	0.3168	1.7759

Device Test: 112.3 Prop Delay LO Off IIM Interlock VIN_14V





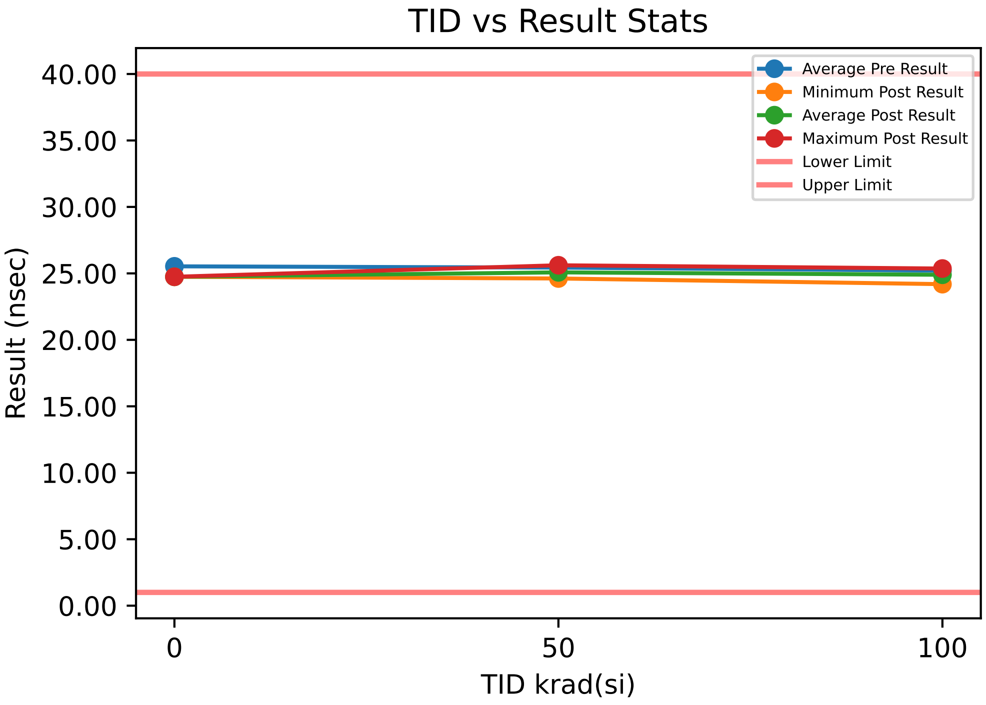
Test Results (Lower Limit = 1.0, Upper Limit = 38.0 (nsec))

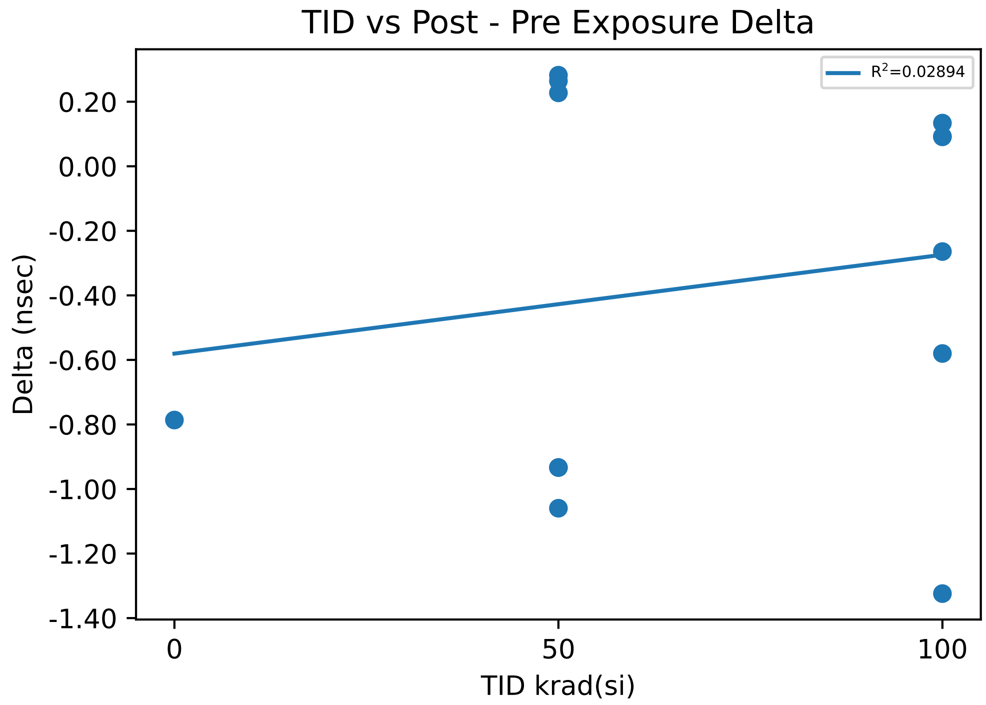
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	25.182	25.94	0.7577
60	50	Biased	26.019	24.965	-1.0543
61	50	Biased	25.265	26.005	0.7407
63	100	Biased	25.277	25.938	0.661
64	100	Biased	26.236	26.125	-0.1109
65	100	Biased	25.354	24.985	-0.369
66	50	Unbiased	26.221	25.264	-0.9572
67	50	Unbiased	25.489	26.16	0.6712
68	50	Unbiased	26.027	24.963	-1.0642
69	100	Unbiased	25.375	25.945	0.5694
70	100	Unbiased	26.323	24.977	-1.3464
71	100	Unbiased	25.698	26.305	0.6068
72	0	Control	26.293	25.488	-0.8059

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.293	26.293	26.293		25.488	25.488	25.488		-0.8059	-0.8059	-0.8059	
50	25.182	25.7	26.221	0.44322	24.963	25.549	26.16	0.54796	-1.0642	-0.15102	0.7577	0.95882
100	25.277	25.711	26.323	0.4646	24.977	25.712	26.305	0.58241	-1.3464	0.0018167	0.661	0.7862

Device Test: 112.4 Prop Delay HO On IIM Interlock VIN_14V





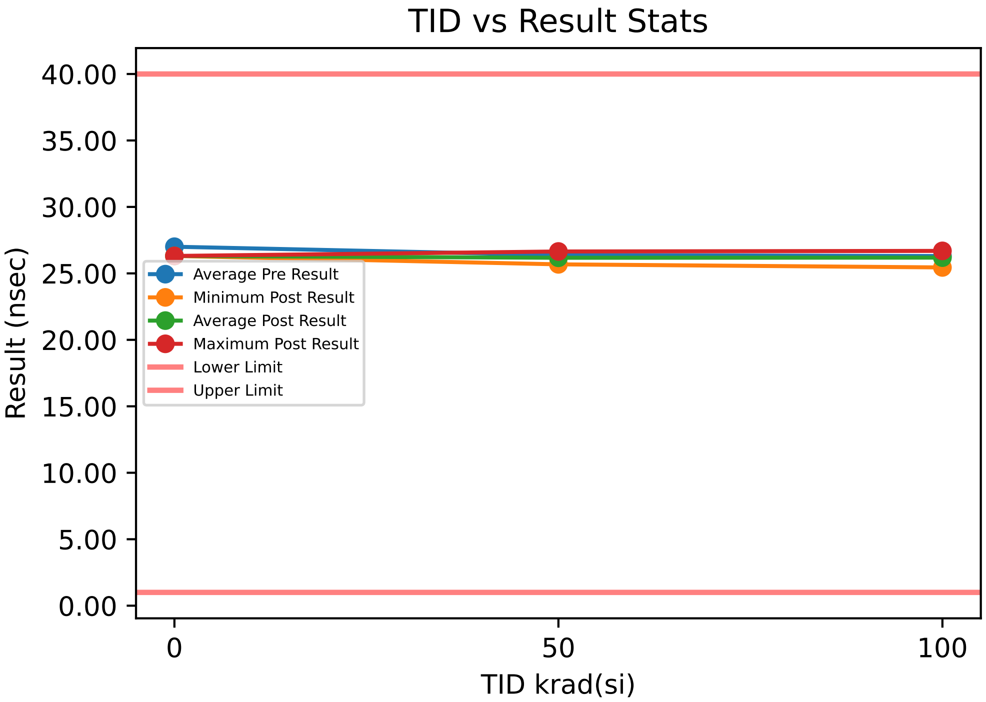
Test Results (Lower Limit = 1.0, Upper Limit = 40.0 (nsec))

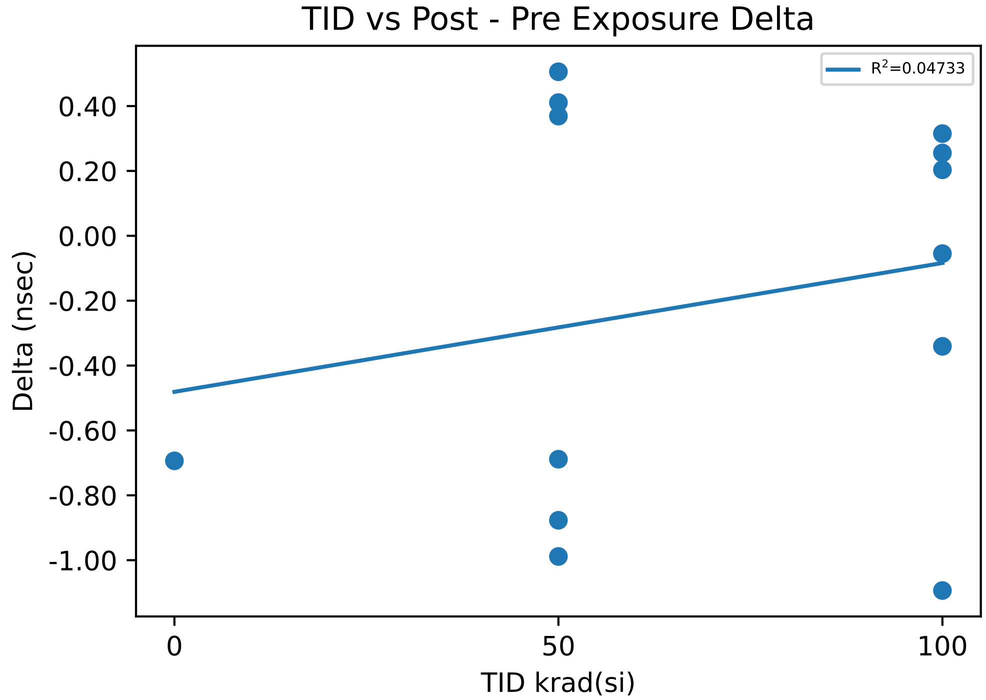
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	25.259	25.541	0.2822
60	50	Biased	25.676	24.616	-1.0596
61	50	Biased	25.383	25.611	0.2275
63	100	Biased	25.084	25.218	0.1338
64	100	Biased	25.629	25.365	-0.2643
65	100	Biased	24.899	24.319	-0.5801
66	50	Unbiased	25.656	24.723	-0.9333
67	50	Unbiased	25.055	25.32	0.2645
68	50	Unbiased	25.585	24.651	-0.9336
69	100	Unbiased	25.048	25.139	0.0912
70	100	Unbiased	25.514	24.19	-1.3241
71	100	Unbiased	25.053	25.145	0.0927
72	0	Control	25.531	24.744	-0.7863

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.531	25.531	25.531		24.744	24.744	24.744		-0.7863	-0.7863	-0.7863	
50	25.055	25.436	25.676	0.24786	24.616	25.077	25.611	0.46439	-1.0596	-0.35872	0.2822	0.67745
100	24.899	25.204	25.629	0.29376	24.19	24.896	25.365	0.50514	-1.3241	-0.30847	0.1338	0.56983

Device Test: 112.5 Prop Delay HO Off IIM Interlock VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

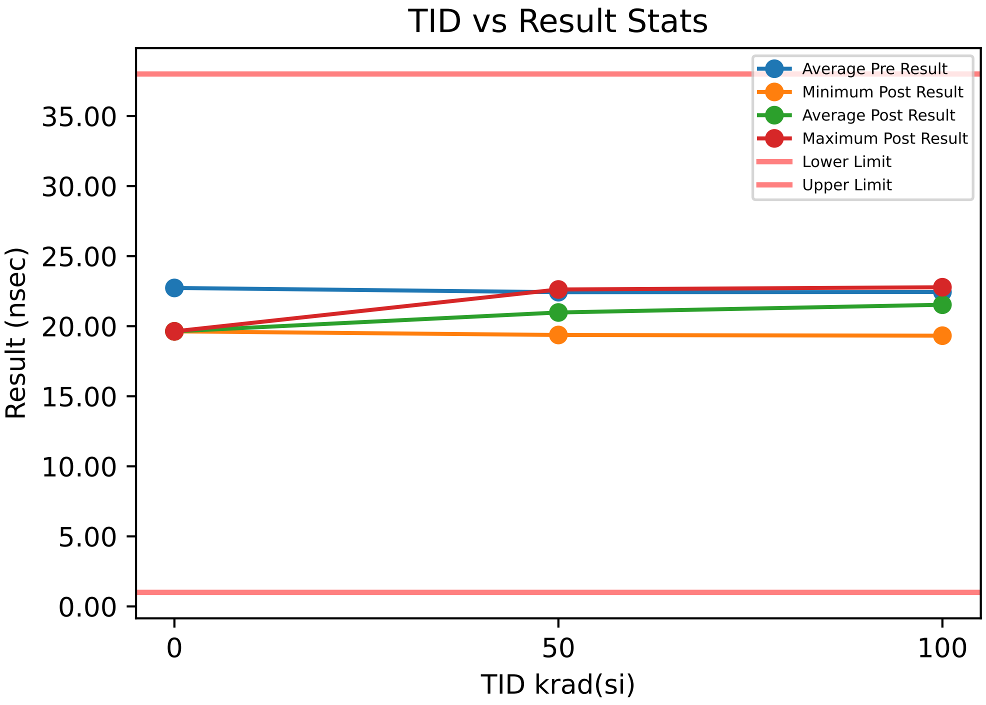
Test Results (Lower Limit = 1.0, Upper Limit = 40.0 (nsec))

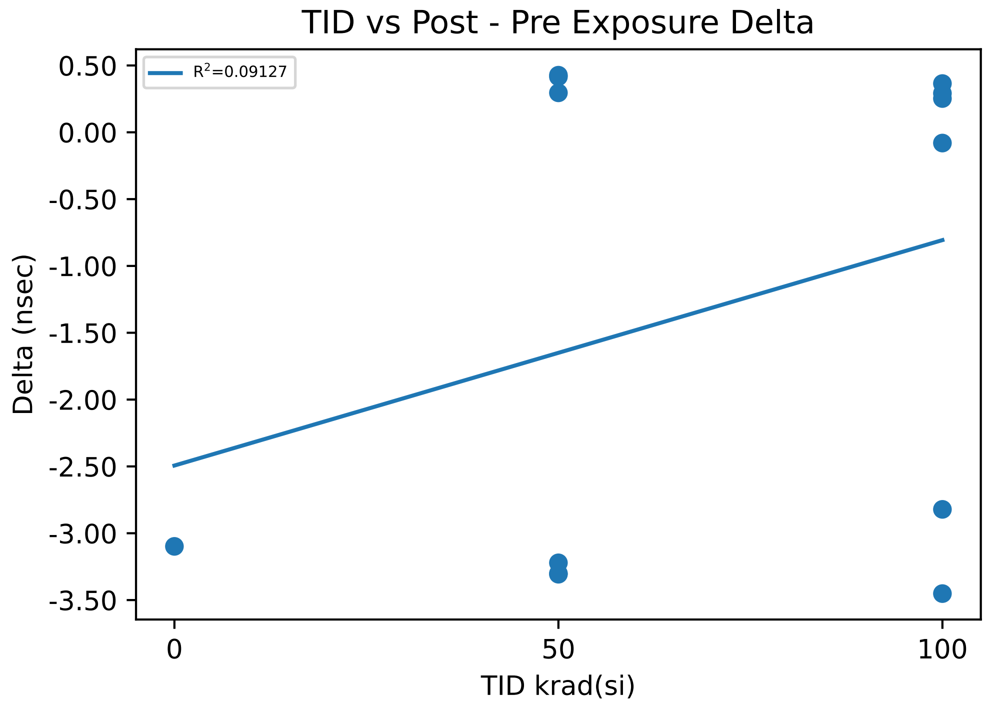
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	26.085	26.591	0.5058
60	50	Biased	26.7	25.712	-0.9885
61	50	Biased	26.237	26.648	0.4107
63	100	Biased	26.277	26.481	0.2036
64	100	Biased	26.747	26.692	-0.0549
65	100	Biased	26.183	25.842	-0.3407
66	50	Unbiased	26.521	25.833	-0.6887
67	50	Unbiased	26.204	26.574	0.3691
68	50	Unbiased	26.557	25.68	-0.877
69	100	Unbiased	25.932	26.187	0.2553
70	100	Unbiased	26.541	25.448	-1.0935
71	100	Unbiased	26.144	26.459	0.3151
72	0	Control	27.006	26.312	-0.6937

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	27.006	27.006	27.006		26.312	26.312	26.312		-0.6937	-0.6937	-0.6937	
50	26.085	26.384	26.7	0.24163	25.68	26.173	26.648	0.47584	-0.9885	-0.21143	0.5058	0.70896
100	25.932	26.304	26.747	0.29399	25.448	26.185	26.692	0.46498	-1.0935	-0.11918	0.3151	0.53582

Device Test: 112.6 Prop Delay LO On IIM Interlock Disable VIN_14V





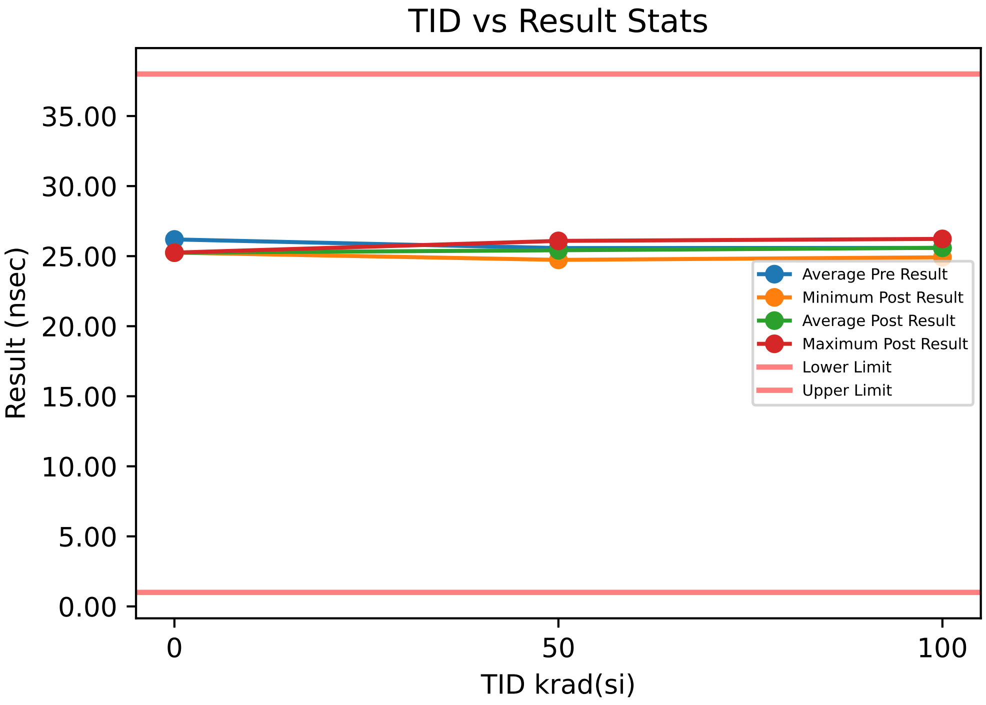
Test Results (Lower Limit = 1.0, Upper Limit = 38.0 (nsec))

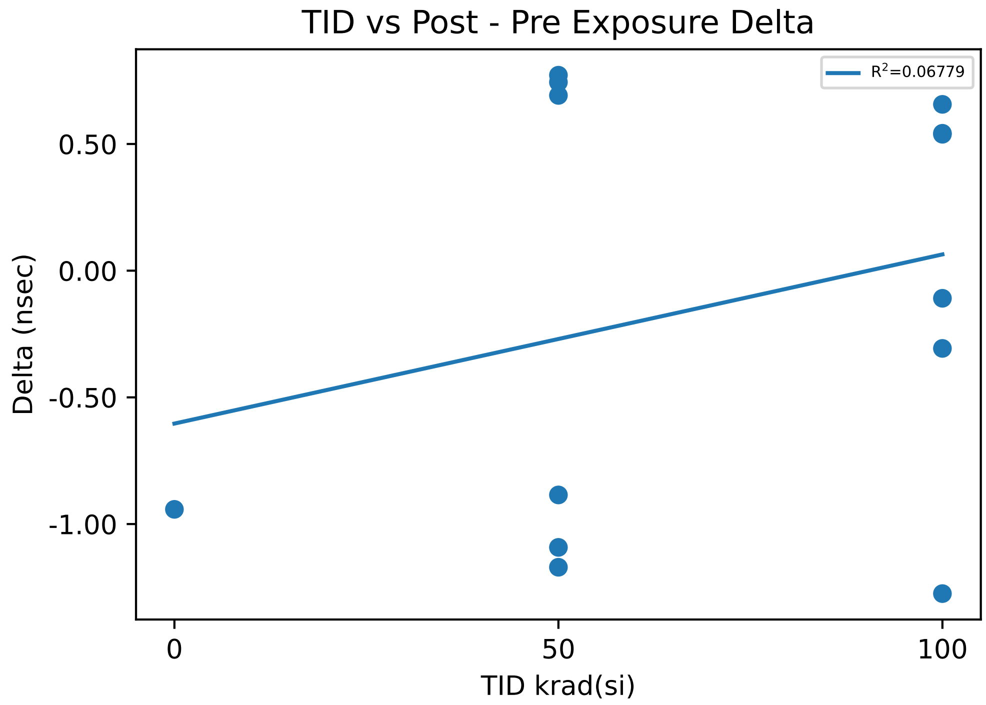
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	22.173	22.588	0.4159
60	50	Biased	22.679	19.372	-3.3066
61	50	Biased	22.071	22.498	0.4272
63	100	Biased	22.156	22.521	0.3647
64	100	Biased	22.758	22.677	-0.0805
65	100	Biased	22.181	19.36	-2.8214
66	50	Unbiased	22.716	19.416	-3.3009
67	50	Unbiased	22.326	22.621	0.2953
68	50	Unbiased	22.598	19.377	-3.2214
69	100	Unbiased	22.275	22.528	0.2526
70	100	Unbiased	22.773	19.322	-3.4516
71	100	Unbiased	22.489	22.78	0.2915
72	0	Control	22.73	19.631	-3.0983

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.73	22.73	22.73		19.631	19.631	19.631		-3.0983	-3.0983	-3.0983	
50	22.071	22.427	22.716	0.27514	19.372	20.979	22.621	1.7428	-3.3066	-1.4484	0.4272	2.0031
100	22.156	22.439	22.773	0.279	19.322	21.531	22.78	1.6997	-3.4516	-0.90745	0.3647	1.7448

Device Test: 112.7 Prop Delay LO Off IIM Interlock Disable VIN_14V





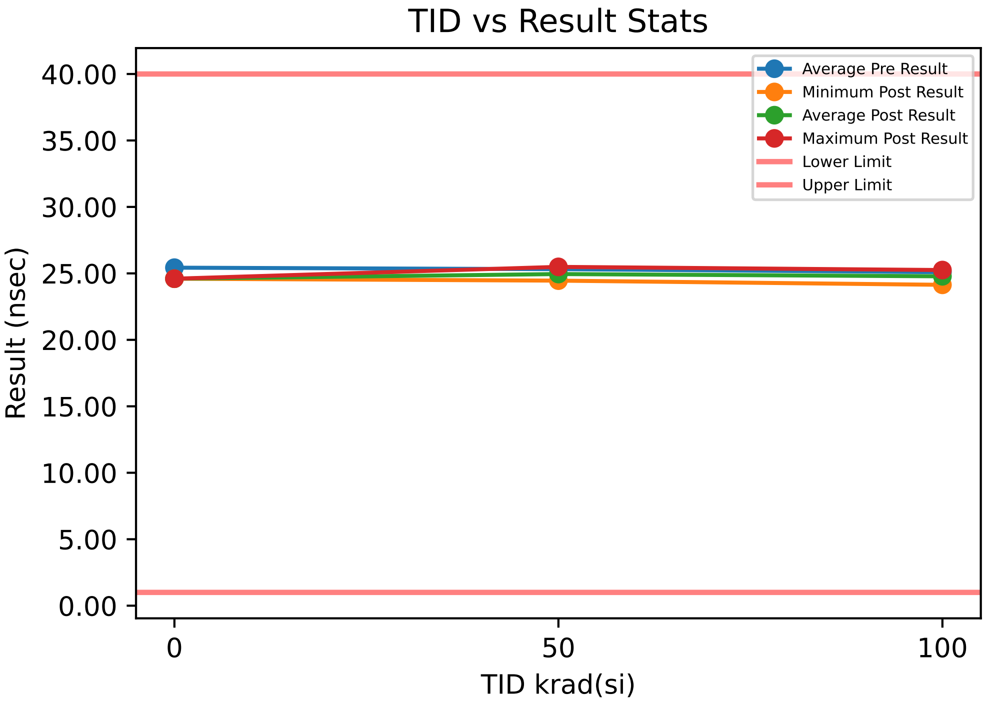
Test Results (Lower Limit = 1.0, Upper Limit = 38.0 (nsec))

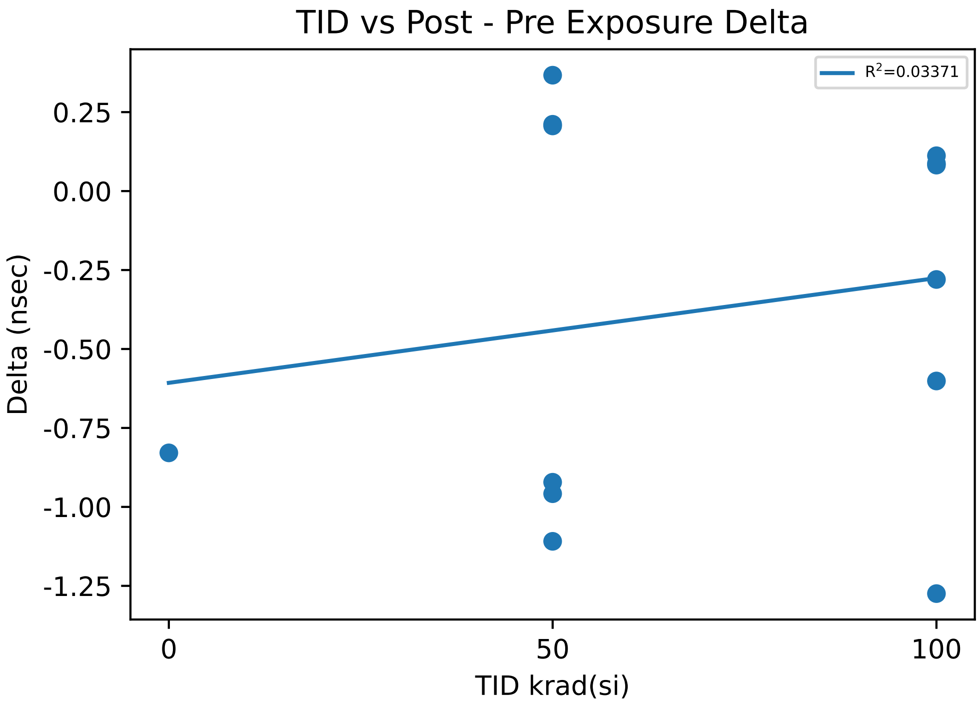
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	25.056	25.828	0.7715
60	50	Biased	25.926	24.834	-1.0921
61	50	Biased	25.128	25.82	0.6917
63	100	Biased	25.151	25.694	0.5423
64	100	Biased	26.137	26.028	-0.109
65	100	Biased	25.231	24.924	-0.3068
66	50	Unbiased	26.1	25.215	-0.8851
67	50	Unbiased	25.345	26.088	0.7439
68	50	Unbiased	25.903	24.733	-1.1705
69	100	Unbiased	25.231	25.77	0.5384
70	100	Unbiased	26.191	24.917	-1.2745
71	100	Unbiased	25.575	26.231	0.6564
72	0	Control	26.193	25.251	-0.942

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.193	26.193	26.193		25.251	25.251	25.251		-0.942	-0.942	-0.942	
50	25.056	25.576	26.1	0.45374	24.733	25.42	26.088	0.57099	-1.1705	-0.15677	0.7715	0.98242
100	25.151	25.586	26.191	0.47139	24.917	25.594	26.231	0.55541	-1.2745	0.0078	0.6564	0.74092

Device Test: 112.8 Prop Delay HO On IIM Interlock Disable VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

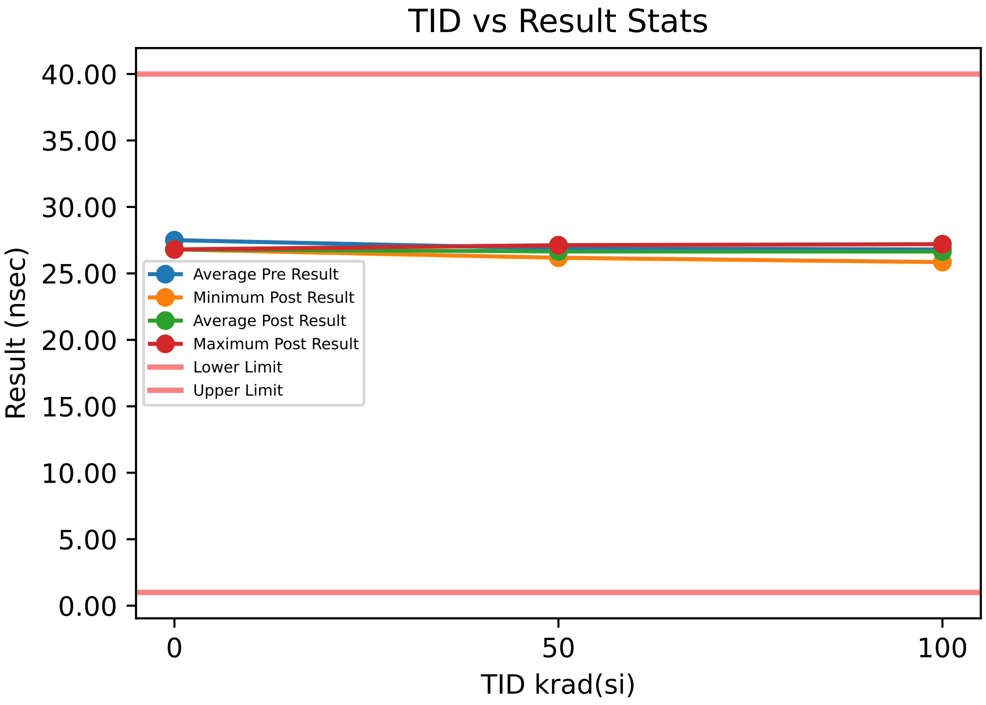
Test Results (Lower Limit = 1.0, Upper Limit = 40.0 (nsec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	25.123	25.49	0.3669
60	50	Biased	25.563	24.454	-1.109
61	50	Biased	25.275	25.482	0.2063
63	100	Biased	24.956	25.068	0.1119
64	100	Biased	25.531	25.251	-0.2799
65	100	Biased	24.805	24.204	-0.6013
66	50	Unbiased	25.544	24.586	-0.9582
67	50	Unbiased	24.896	25.107	0.2115
68	50	Unbiased	25.502	24.58	-0.9219
69	100	Unbiased	24.92	25.007	0.0875
70	100	Unbiased	25.414	24.14	-1.2745
71	100	Unbiased	24.926	25.008	0.0822
72	0	Control	25.429	24.6	-0.8289

Test Statistics (nsec)

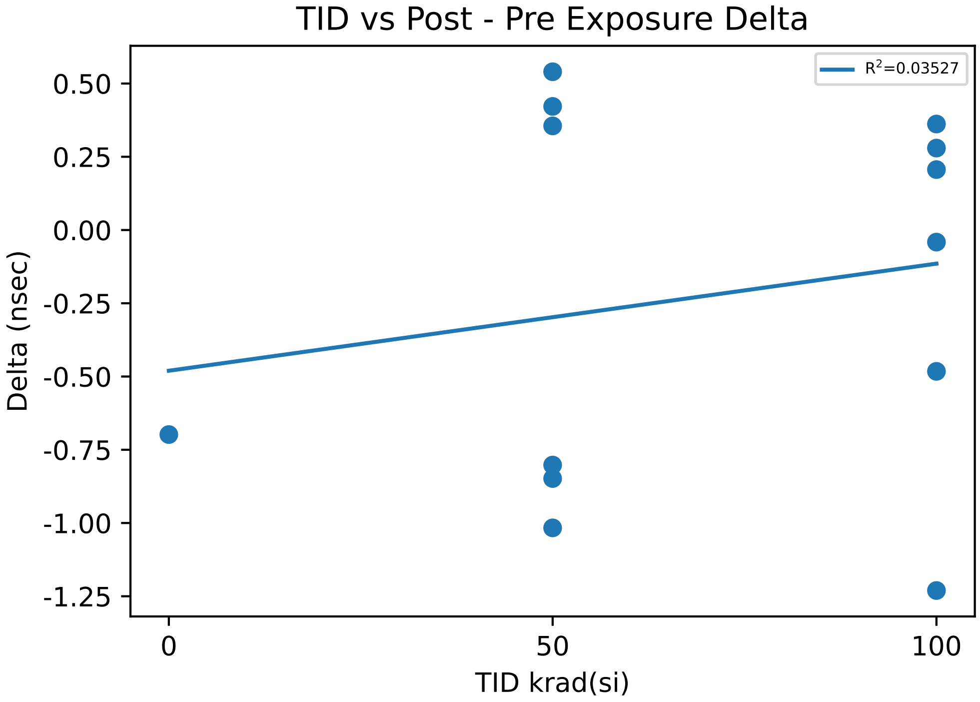
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.429	25.429	25.429		24.6	24.6	24.6		-0.8289	-0.8289	-0.8289	
50	24.896	25.317	25.563	0.26957	24.454	24.95	25.49	0.47198	-1.109	-0.3674	0.3669	0.69425
100	24.805	25.092	25.531	0.3015	24.14	24.78	25.251	0.47969	-1.2745	-0.31235	0.1119	0.54878

Device Test: 112.9 Prop Delay HO Off IIM Interlock Disable VIN_14V


TID vs Result Stats

Test Results (Lower Limit = 1.0, Upper Limit = 40.0 (nsec))

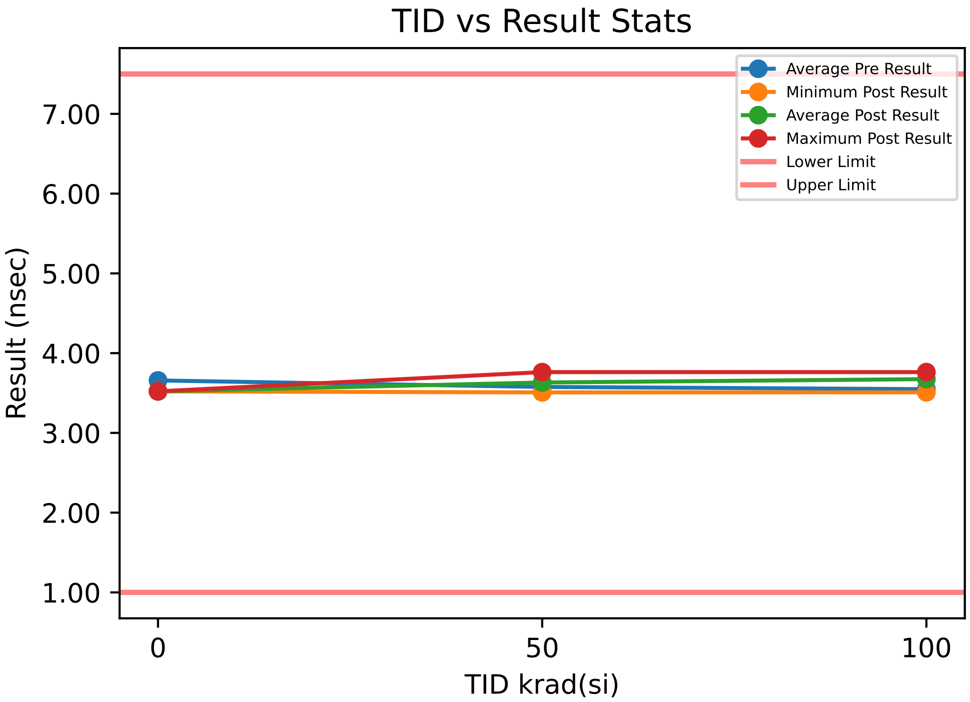
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	26.584	27.124	0.5402
60	50	Biased	27.195	26.178	-1.0166
61	50	Biased	26.697	27.119	0.4219
63	100	Biased	26.753	26.959	0.2063
64	100	Biased	27.241	27.2	-0.0412
65	100	Biased	26.686	26.203	-0.4824
66	50	Unbiased	27.025	26.177	-0.8481
67	50	Unbiased	26.723	27.078	0.3554
68	50	Unbiased	27.048	26.246	-0.8022
69	100	Unbiased	26.403	26.683	0.2797
70	100	Unbiased	27.081	25.851	-1.2304
71	100	Unbiased	26.641	27.003	0.3618
72	0	Control	27.501	26.803	-0.6981

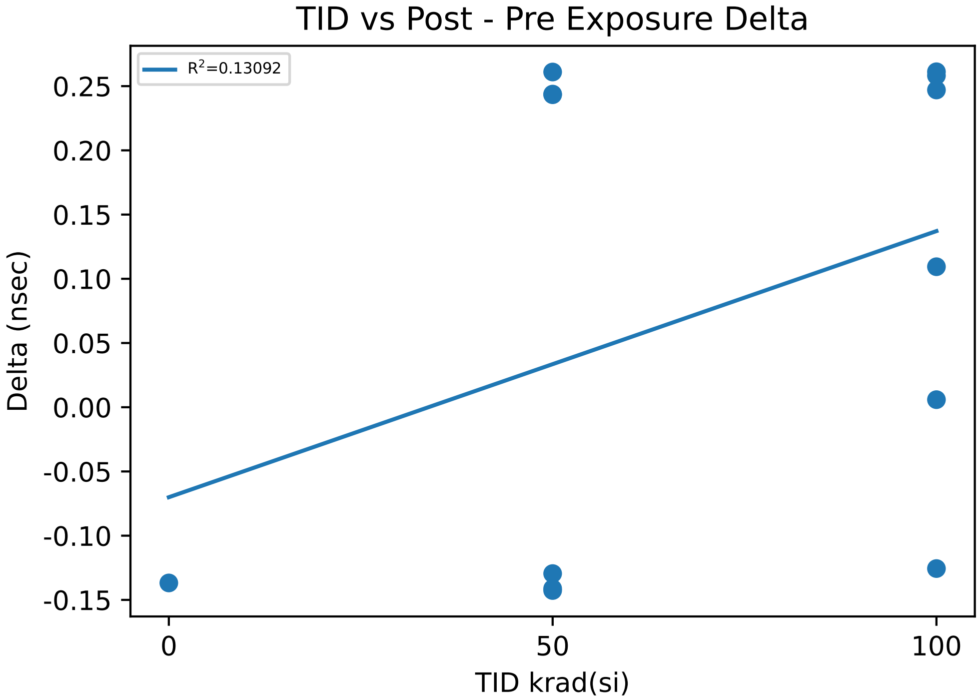

TID vs Post - Pre Exposure Delta

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	27.501	27.501	27.501		26.803	26.803	26.803		-0.6981	-0.6981	-0.6981	
50	26.584	26.879	27.195	0.2428	26.177	26.654	27.124	0.4973	-1.0166	-0.2249	0.5402	0.73334
100	26.403	26.801	27.241	0.30704	25.851	26.65	27.2	0.52196	-1.2304	-0.15103	0.3618	0.61043

Device Test: 115.0 Rise Time HO VIN_10V





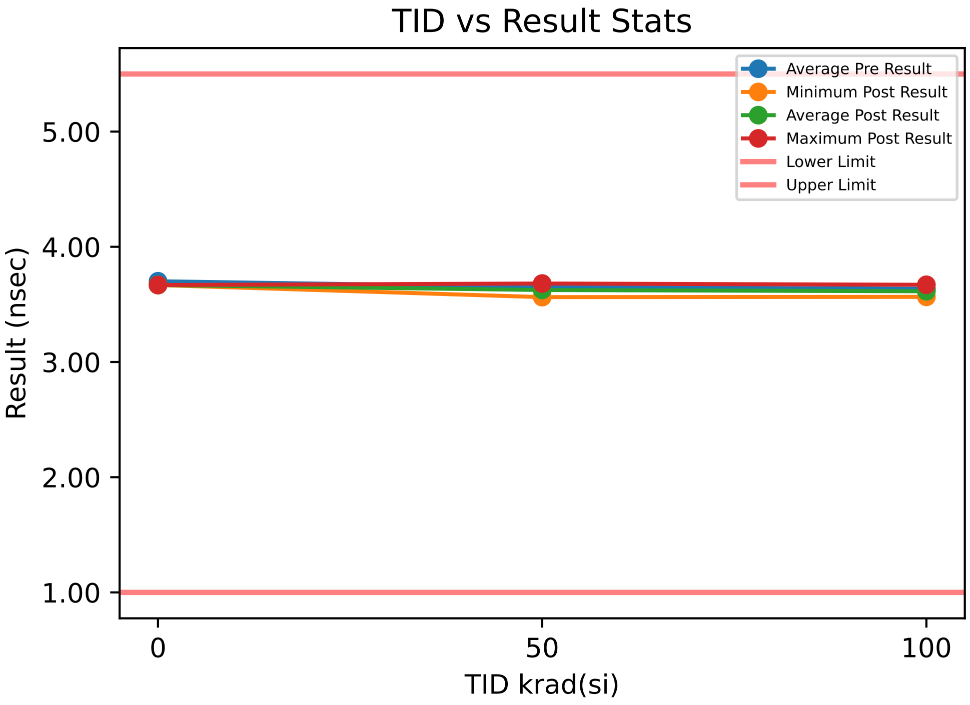
Test Results (Lower Limit = 1.0, Upper Limit = 7.5 (nsec))

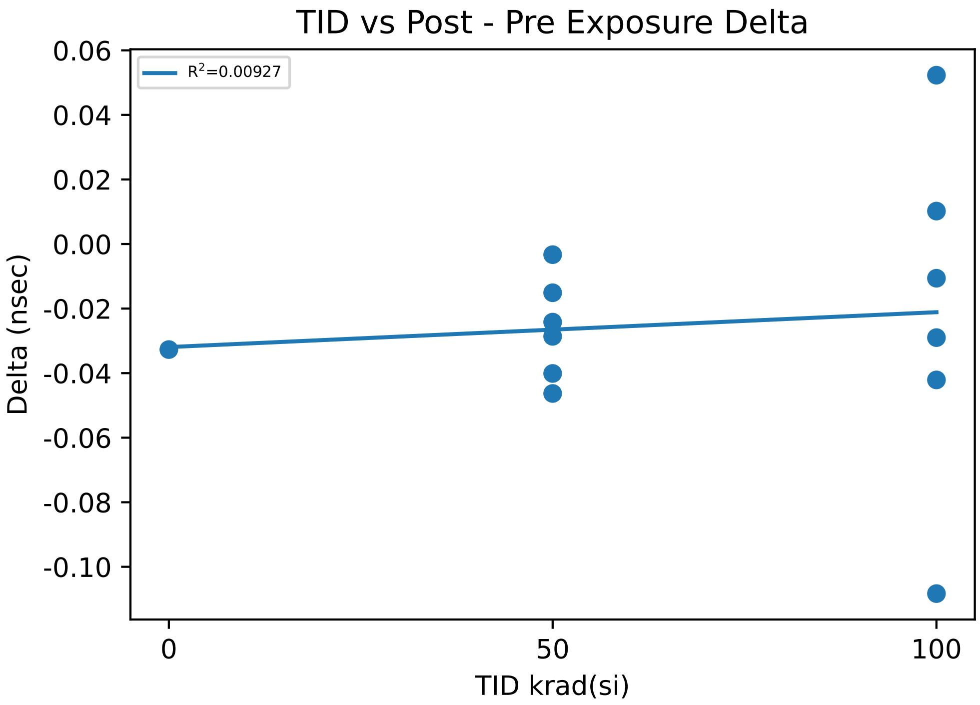
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.5056	3.7494	0.2438
60	50	Biased	3.6503	3.5076	-0.1427
61	50	Biased	3.5031	3.7464	0.2433
63	100	Biased	3.4965	3.7547	0.2582
64	100	Biased	3.6526	3.762	0.1094
65	100	Biased	3.5026	3.5085	0.0059
66	50	Unbiased	3.6466	3.5171	-0.1295
67	50	Unbiased	3.501	3.762	0.261
68	50	Unbiased	3.6503	3.5091	-0.1412
69	100	Unbiased	3.4954	3.7566	0.2612
70	100	Unbiased	3.6495	3.5239	-0.1256
71	100	Unbiased	3.4921	3.7391	0.247
72	0	Control	3.6576	3.5208	-0.1368

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6576	3.6576	3.6576		3.5208	3.5208	3.5208		-0.1368	-0.1368	-0.1368	
50	3.501	3.5762	3.6503	0.079901	3.5076	3.6319	3.762	0.13233	-0.1427	0.055783	0.261	0.2122
100	3.4921	3.5481	3.6526	0.07981	3.5085	3.6741	3.762	0.12267	-0.1256	0.12602	0.2612	0.16025

Device Test: 115.1 Fall Time HO VIN_10V





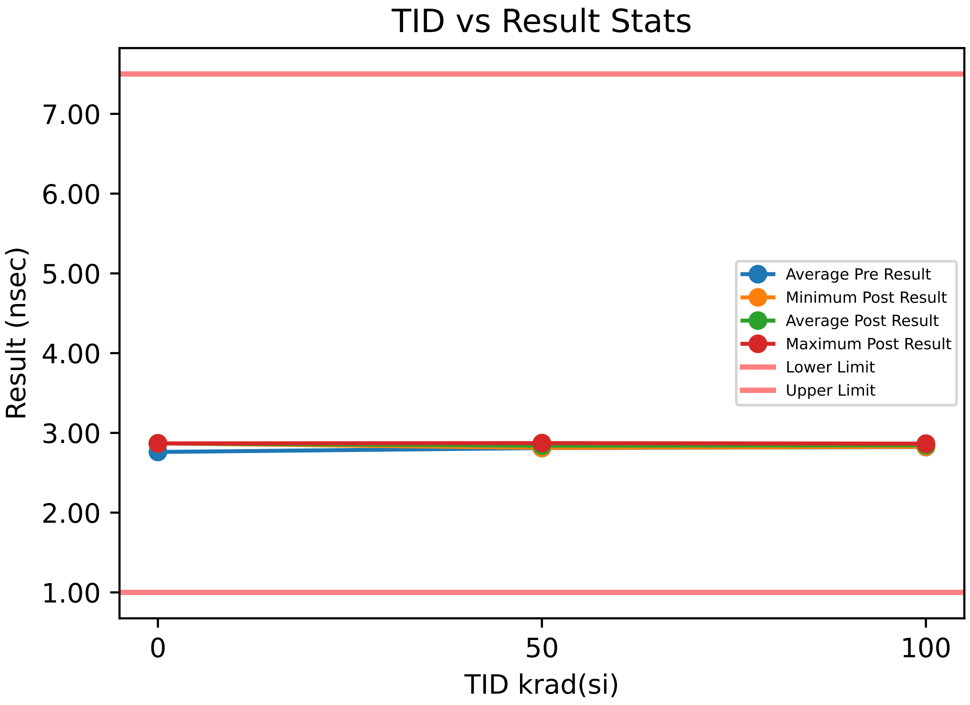
Test Results (Lower Limit = 1.0, Upper Limit = 5.5 (nsec))

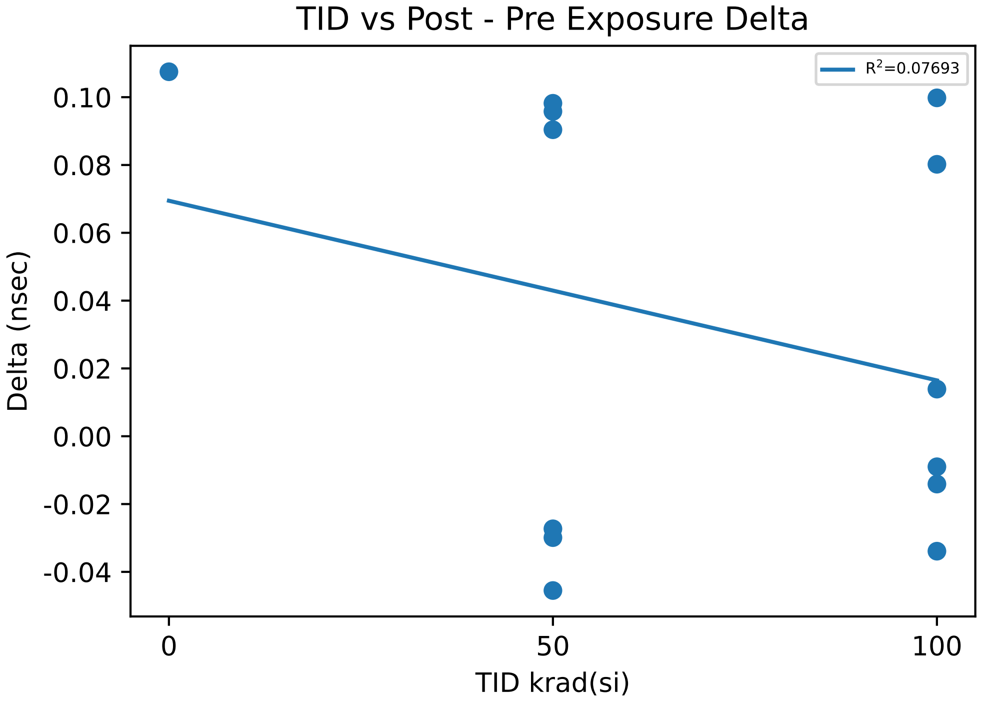
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.5955	3.5922	-0.0033
60	50	Biased	3.6963	3.6812	-0.0151
61	50	Biased	3.6094	3.5631	-0.0463
63	100	Biased	3.6062	3.5956	-0.0106
64	100	Biased	3.6929	3.5846	-0.1083
65	100	Biased	3.6025	3.6548	0.0523
66	50	Unbiased	3.7017	3.6775	-0.0242
67	50	Unbiased	3.6168	3.5767	-0.0401
68	50	Unbiased	3.6872	3.6586	-0.0286
69	100	Unbiased	3.6027	3.6129	0.0102
70	100	Unbiased	3.6992	3.6702	-0.029
71	100	Unbiased	3.6075	3.5654	-0.0421
72	0	Control	3.7009	3.6682	-0.0327

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7009	3.7009	3.7009		3.6682	3.6682	3.6682		-0.0327	-0.0327	-0.0327	
50	3.5955	3.6511	3.7017	0.048813	3.5631	3.6249	3.6812	0.053449	-0.0463	-0.026267	-0.0033	0.01584
100	3.6025	3.6352	3.6992	0.047242	3.5654	3.6139	3.6702	0.040961	-0.1083	-0.02125	0.0523	0.054009

Device Test: 115.2 Rise Time LO VIN_10V





Test Results (Lower Limit = 1.0, Upper Limit = 7.5 (nsec))

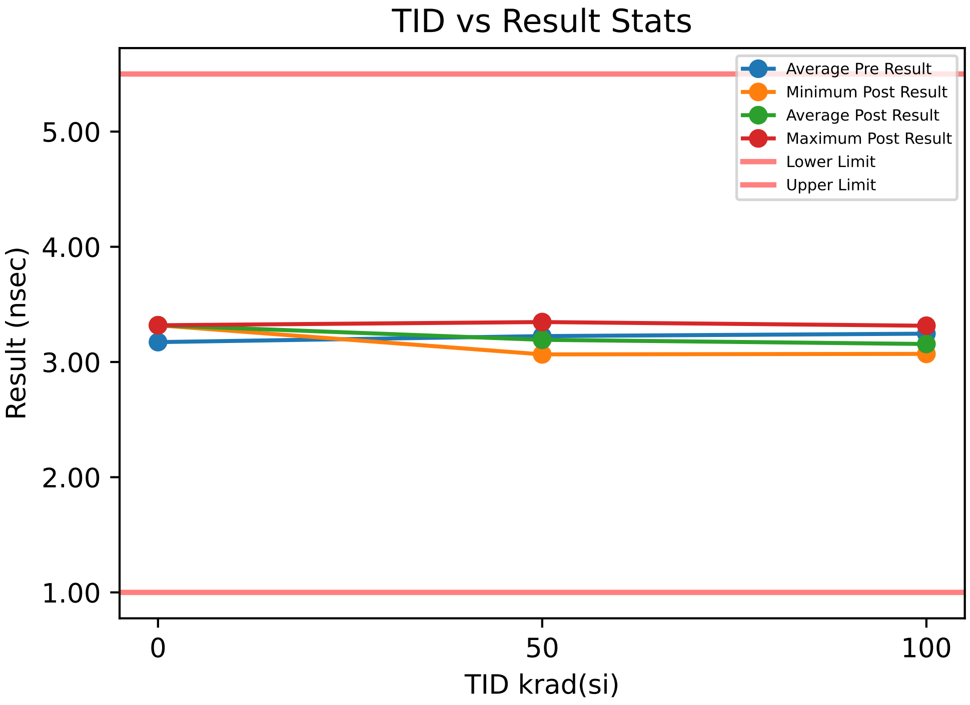
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.8517	2.8218	-0.0299
60	50	Biased	2.7737	2.8719	0.0982
61	50	Biased	2.8575	2.812	-0.0455
63	100	Biased	2.8514	2.8424	-0.009
64	100	Biased	2.757	2.8372	0.0802
65	100	Biased	2.8509	2.8648	0.0139
66	50	Unbiased	2.767	2.8574	0.0904
67	50	Unbiased	2.8555	2.8282	-0.0273
68	50	Unbiased	2.7516	2.8474	0.0958
69	100	Unbiased	2.8593	2.8254	-0.0339
70	100	Unbiased	2.763	2.8628	0.0998
71	100	Unbiased	2.8535	2.8394	-0.0141
72	0	Control	2.7609	2.8684	0.1075

Test Statistics (nsec)

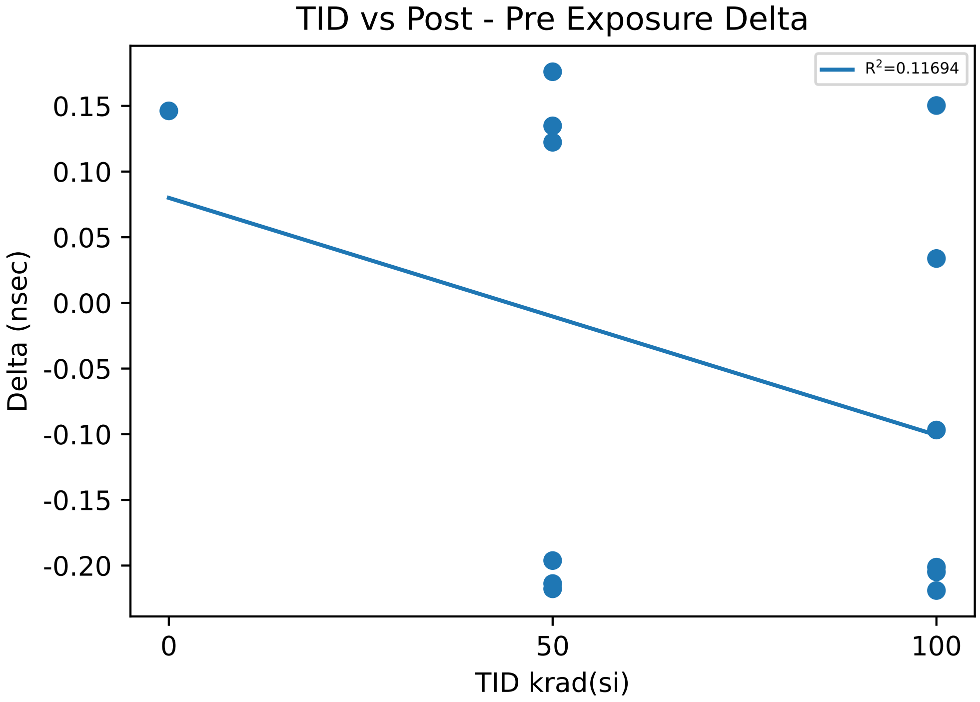
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7609	2.7609	2.7609		2.8684	2.8684	2.8684		0.1075	0.1075	0.1075	
50	2.7516	2.8095	2.8575	0.050281	2.812	2.8398	2.8719	0.022932	-0.0455	0.030283	0.0982	0.070993
100	2.757	2.8225	2.8593	0.048554	2.8254	2.8453	2.8648	0.015436	-0.0339	0.022817	0.0998	0.054572

Device Test: 115.3 Fall Time LO VIN_10V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



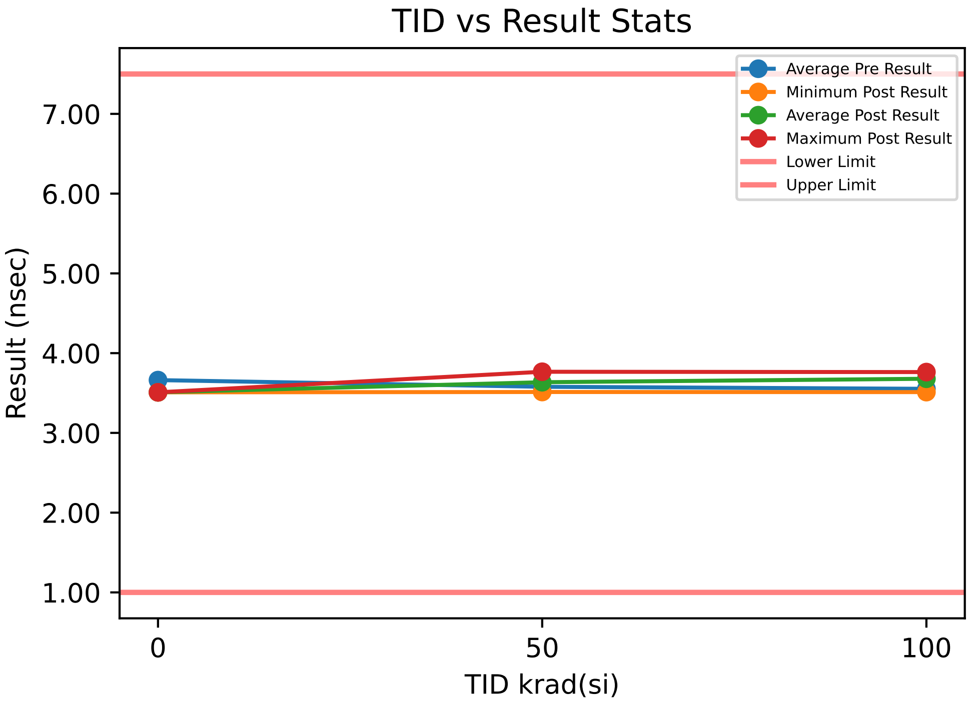
Test Results (Lower Limit = 1.0, Upper Limit = 5.5 (nsec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.271	3.0748	-0.1962
60	50	Biased	3.1763	3.2986	0.1223
61	50	Biased	3.2839	3.0662	-0.2177
63	100	Biased	3.2834	3.0822	-0.2012
64	100	Biased	3.1686	3.0718	-0.0968
65	100	Biased	3.272	3.3058	0.0338
66	50	Unbiased	3.1708	3.3468	0.176
67	50	Unbiased	3.2883	3.0746	-0.2137
68	50	Unbiased	3.1594	3.2942	0.1348
69	100	Unbiased	3.2894	3.0704	-0.219
70	100	Unbiased	3.1645	3.3148	0.1503
71	100	Unbiased	3.2973	3.0925	-0.2048
72	0	Control	3.1727	3.3189	0.1462

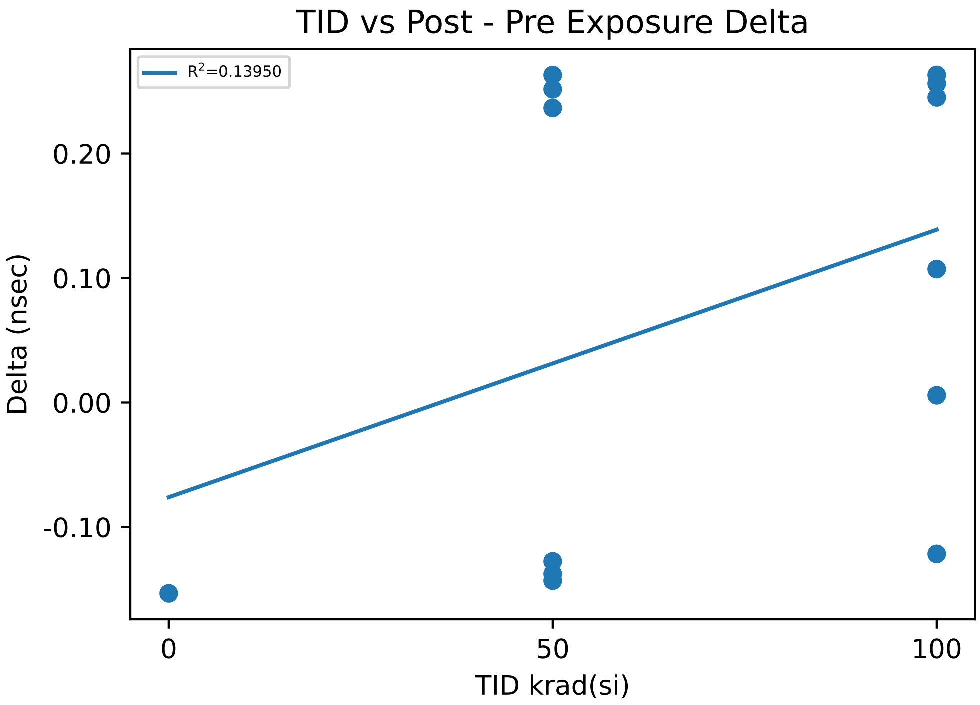
Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.1727	3.1727	3.1727		3.3189	3.3189	3.3189		0.1462	0.1462	0.1462	
50	3.1594	3.2249	3.2883	0.061975	3.0662	3.1925	3.3468	0.1335	-0.2177	-0.032417	0.176	0.1946
100	3.1645	3.2459	3.2973	0.062005	3.0704	3.1562	3.3148	0.11963	-0.219	-0.089617	0.1503	0.15186

Device Test: 116.0 Rise Time HO VIN_12V



TID vs Result Stats



TID vs Post - Pre Exposure Delta

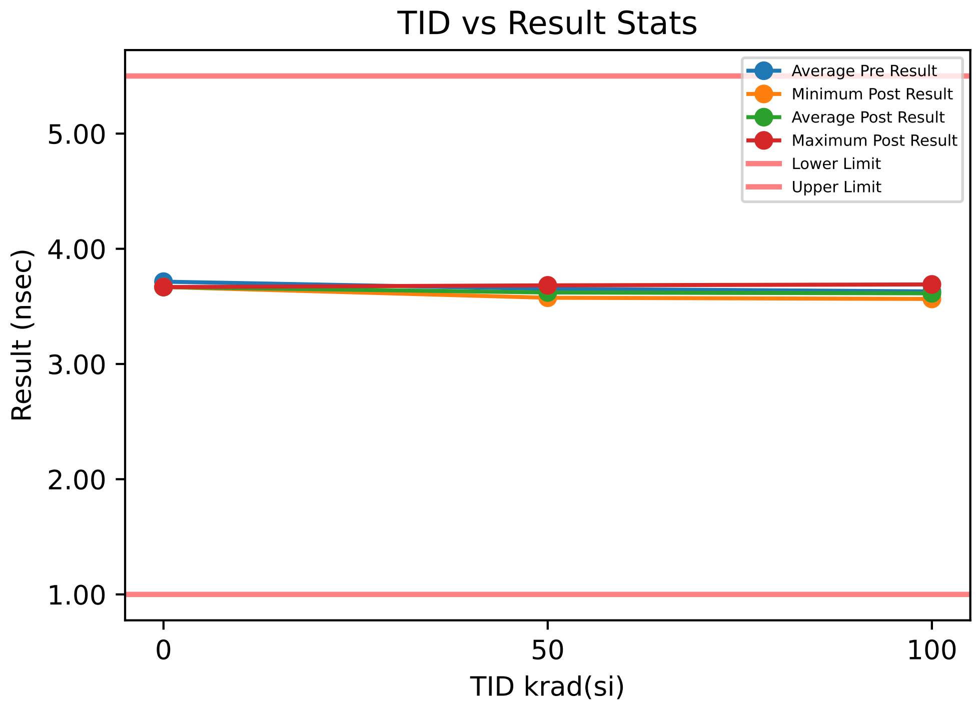
Test Results (Lower Limit = 1.0, Upper Limit = 7.5 (nsec))

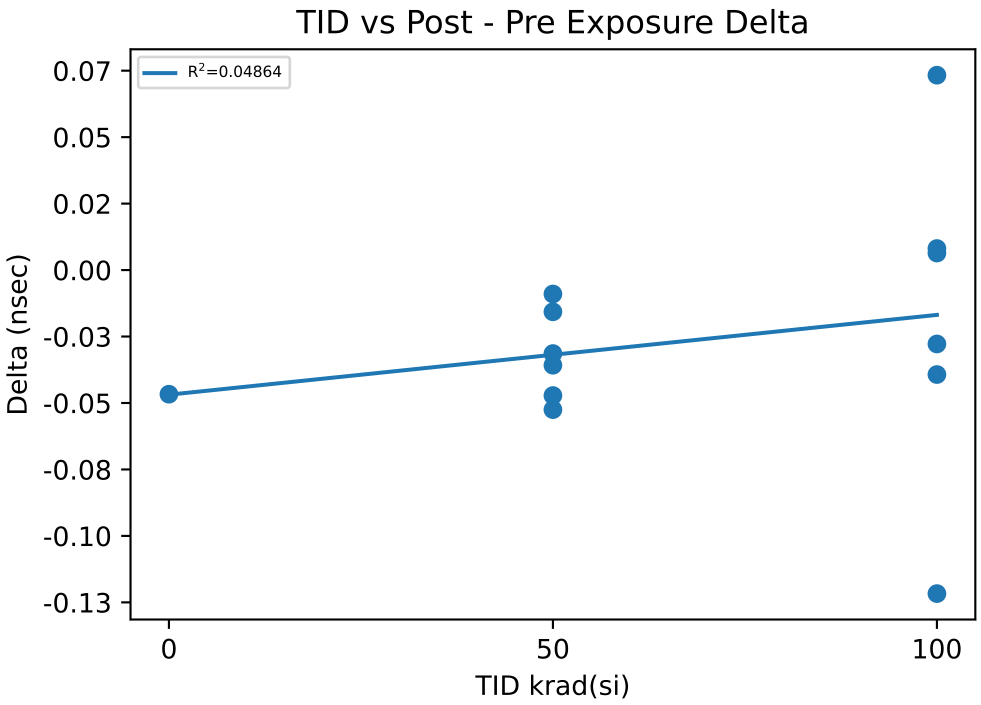
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.5064	3.743	0.2366
60	50	Biased	3.6523	3.5146	-0.1377
61	50	Biased	3.5018	3.7534	0.2516
63	100	Biased	3.5117	3.7568	0.2451
64	100	Biased	3.652	3.7592	0.1072
65	100	Biased	3.5056	3.5114	0.0058
66	50	Unbiased	3.6492	3.5216	-0.1276
67	50	Unbiased	3.5035	3.7665	0.263
68	50	Unbiased	3.6558	3.5127	-0.1431
69	100	Unbiased	3.4994	3.7625	0.2631
70	100	Unbiased	3.6539	3.5323	-0.1216
71	100	Unbiased	3.4934	3.7496	0.2562
72	0	Control	3.6619	3.5086	-0.1533

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6619	3.6619	3.6619		3.5086	3.5086	3.5086		-0.1533	-0.1533	-0.1533	
50	3.5018	3.5782	3.6558	0.081395	3.5127	3.6353	3.7665	0.1306	-0.1431	0.057133	0.263	0.21194
100	3.4934	3.5527	3.6539	0.077921	3.5114	3.6786	3.7625	0.1217	-0.1216	0.12597	0.2631	0.15877

Device Test: 116.1 Fall Time HO VIN_12V





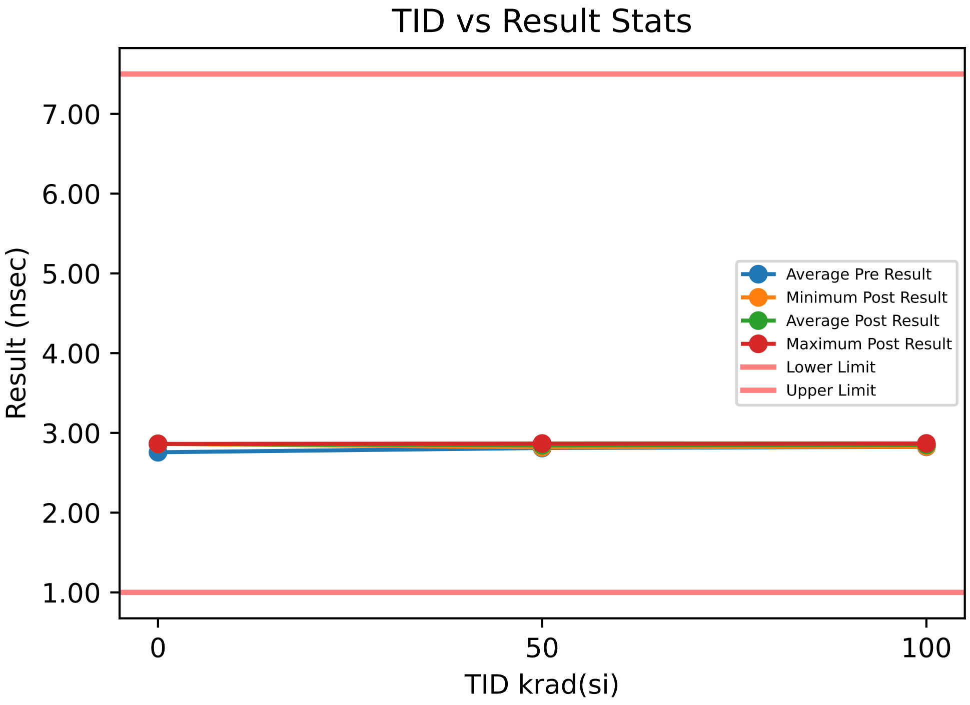
Test Results (Lower Limit = 1.0, Upper Limit = 5.5 (nsec))

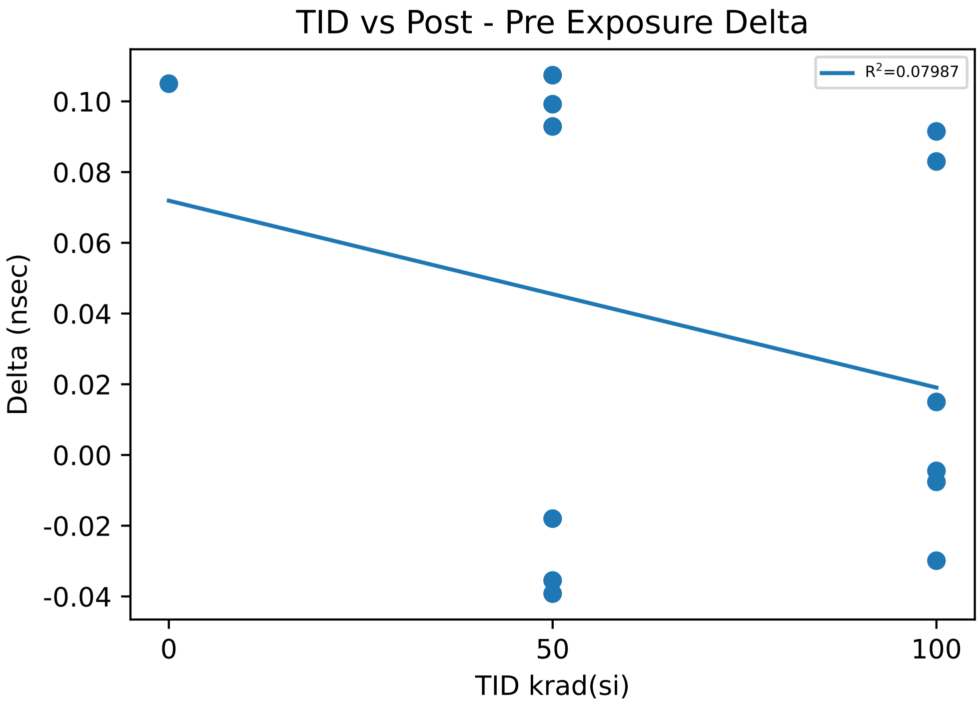
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.6016	3.5859	-0.0157
60	50	Biased	3.7018	3.6546	-0.0472
61	50	Biased	3.6108	3.575	-0.0358
63	100	Biased	3.6193	3.58	-0.0393
64	100	Biased	3.6905	3.5688	-0.1217
65	100	Biased	3.5924	3.6657	0.0733
66	50	Unbiased	3.6917	3.6827	-0.009
67	50	Unbiased	3.6126	3.5812	-0.0314
68	50	Unbiased	3.6968	3.6443	-0.0525
69	100	Unbiased	3.6017	3.6098	0.0081
70	100	Unbiased	3.6843	3.6907	0.0064
71	100	Unbiased	3.5925	3.5647	-0.0278
72	0	Control	3.7148	3.6681	-0.0467

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7148	3.7148	3.7148		3.6681	3.6681	3.6681		-0.0467	-0.0467	-0.0467	
50	3.6016	3.6525	3.7018	0.048685	3.575	3.6206	3.6827	0.045629	-0.0525	-0.031933	-0.009	0.017092
100	3.5924	3.6301	3.6905	0.045484	3.5647	3.6133	3.6907	0.053291	-0.1217	-0.016833	0.0733	0.064665

Device Test: 116.2 Rise Time LO VIN_12V





Test Results (Lower Limit = 1.0, Upper Limit = 7.5 (nsec))

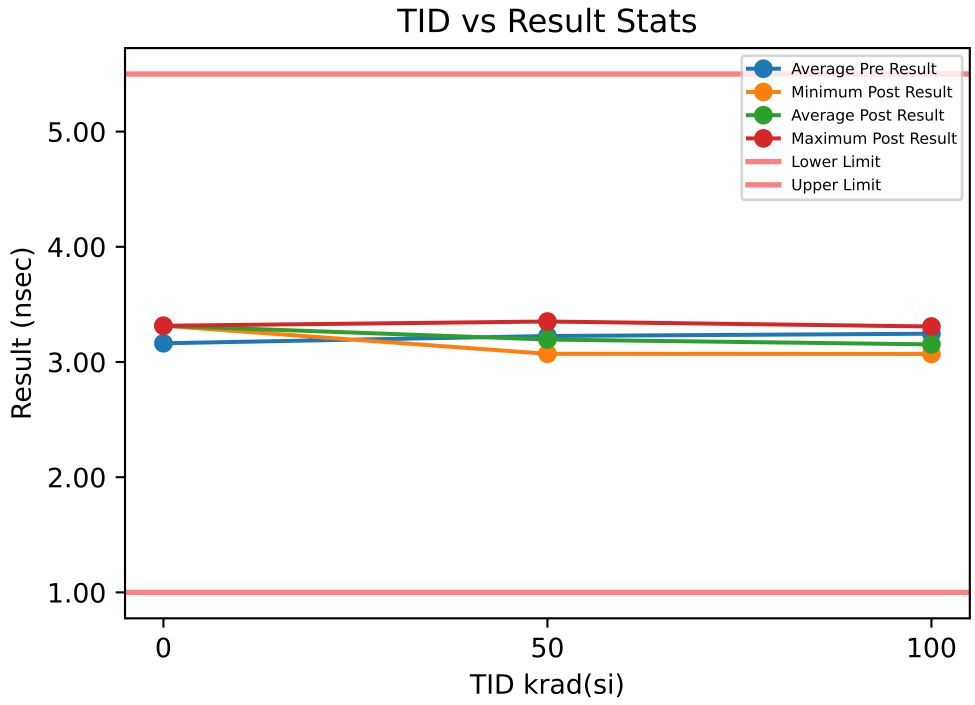
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.8546	2.8191	-0.0355
60	50	Biased	2.7737	2.8666	0.0929
61	50	Biased	2.8582	2.819	-0.0392
63	100	Biased	2.8575	2.8499	-0.0076
64	100	Biased	2.7601	2.8431	0.083
65	100	Biased	2.8528	2.8678	0.015
66	50	Unbiased	2.7675	2.8667	0.0992
67	50	Unbiased	2.8544	2.8364	-0.018
68	50	Unbiased	2.753	2.8604	0.1074
69	100	Unbiased	2.8587	2.8288	-0.0299
70	100	Unbiased	2.7638	2.8553	0.0915
71	100	Unbiased	2.8572	2.8527	-0.0045
72	0	Control	2.7571	2.8621	0.105

Test Statistics (nsec)

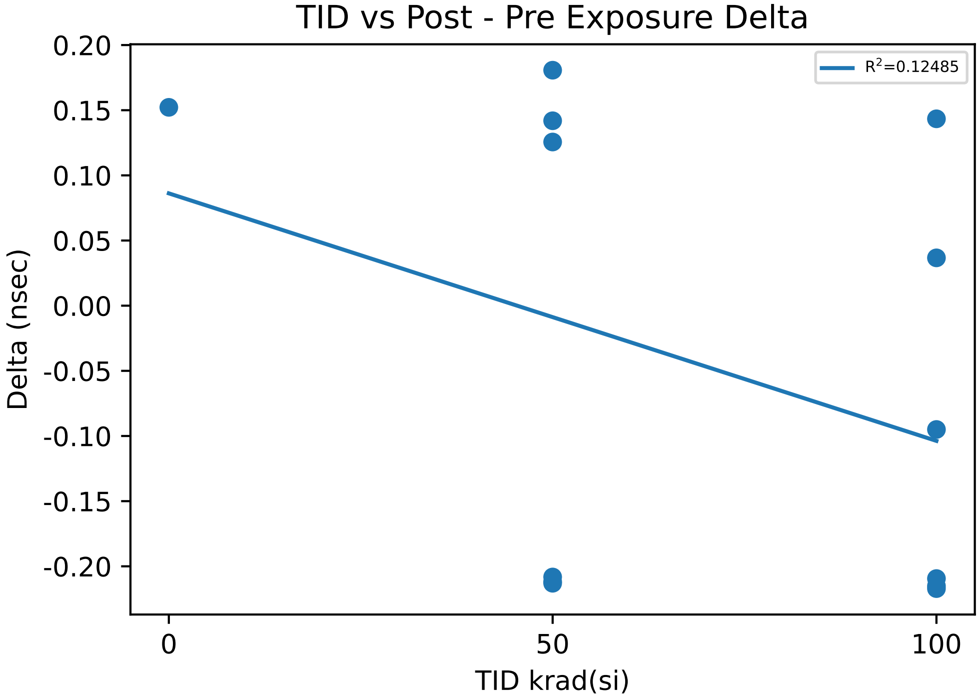
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7571	2.7571	2.7571		2.8621	2.8621	2.8621		0.105	0.105	0.105	
50	2.753	2.8102	2.8582	0.050312	2.819	2.8447	2.8667	0.022781	-0.0392	0.034467	0.1074	0.07211
100	2.7601	2.825	2.8587	0.048906	2.8288	2.8496	2.8678	0.013026	-0.0299	0.024583	0.0915	0.05066

Device Test: 116.3 Fall Time LO VIN_12V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



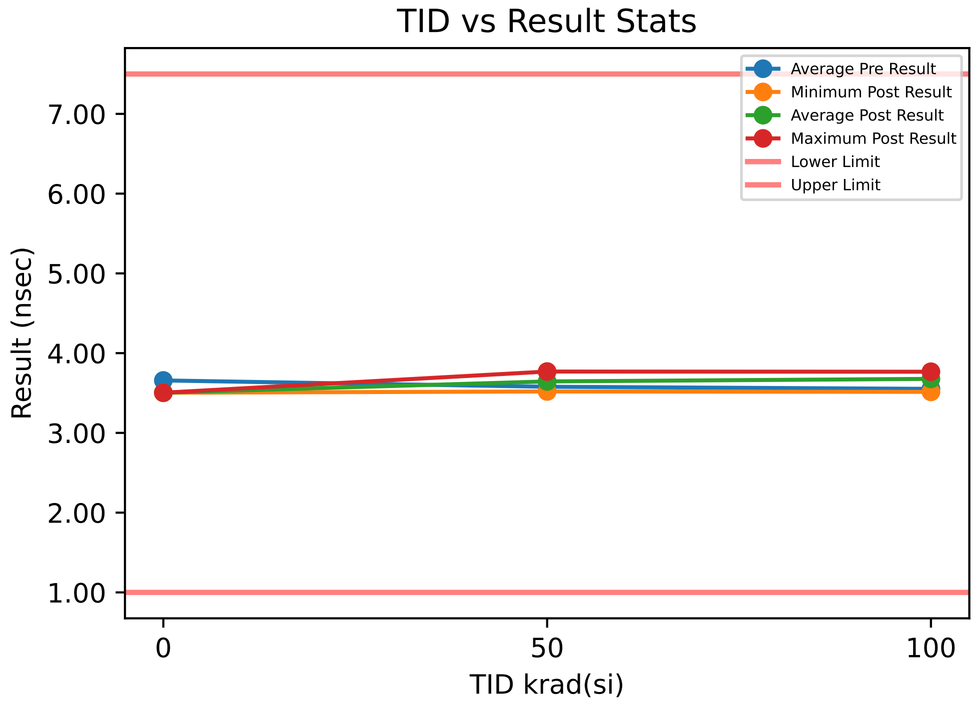
Test Results (Lower Limit = 1.0, Upper Limit = 5.5 (nsec))

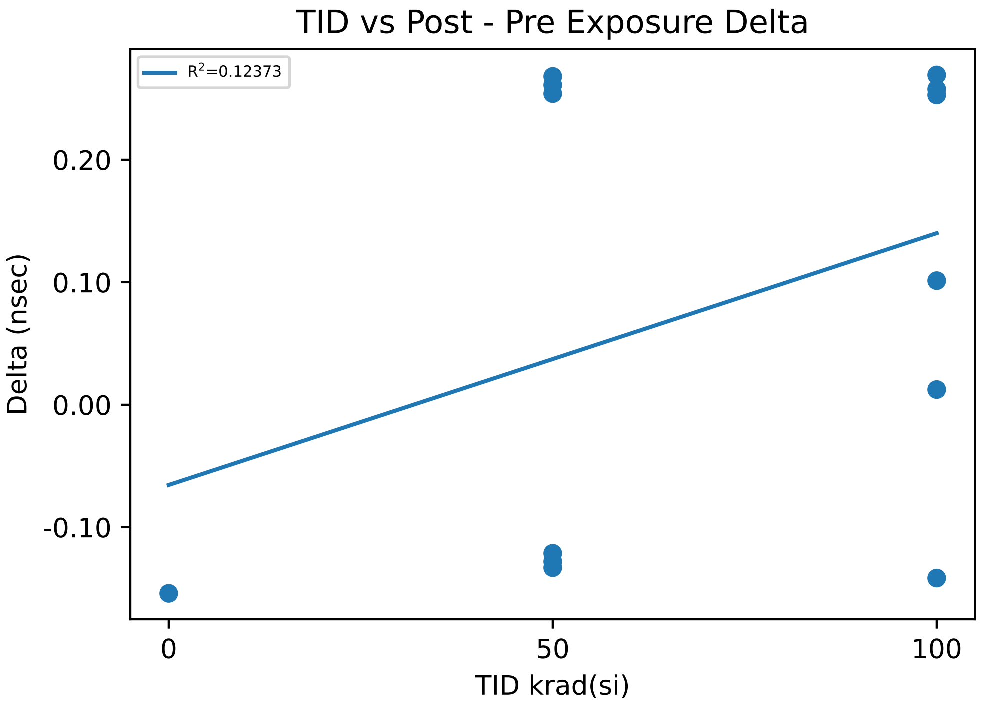
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.2793	3.0711	-0.2082
60	50	Biased	3.1754	3.301	0.1256
61	50	Biased	3.2832	3.0715	-0.2117
63	100	Biased	3.286	3.0766	-0.2094
64	100	Biased	3.1652	3.0702	-0.095
65	100	Biased	3.2716	3.3083	0.0367
66	50	Unbiased	3.1708	3.3515	0.1807
67	50	Unbiased	3.2897	3.0767	-0.213
68	50	Unbiased	3.1559	3.2978	0.1419
69	100	Unbiased	3.2869	3.0718	-0.2151
70	100	Unbiased	3.1636	3.307	0.1434
71	100	Unbiased	3.3001	3.083	-0.2171
72	0	Control	3.1624	3.3146	0.1522

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.1624	3.1624	3.1624		3.3146	3.3146	3.3146		0.1522	0.1522	0.1522	
50	3.1559	3.2257	3.2897	0.064329	3.0711	3.1949	3.3515	0.13483	-0.213	-0.030783	0.1807	0.1982
100	3.1636	3.2456	3.3001	0.063517	3.0702	3.1528	3.3083	0.12002	-0.2171	-0.09275	0.1434	0.15269

Device Test: 117.0 Rise Time HO VIN_14V





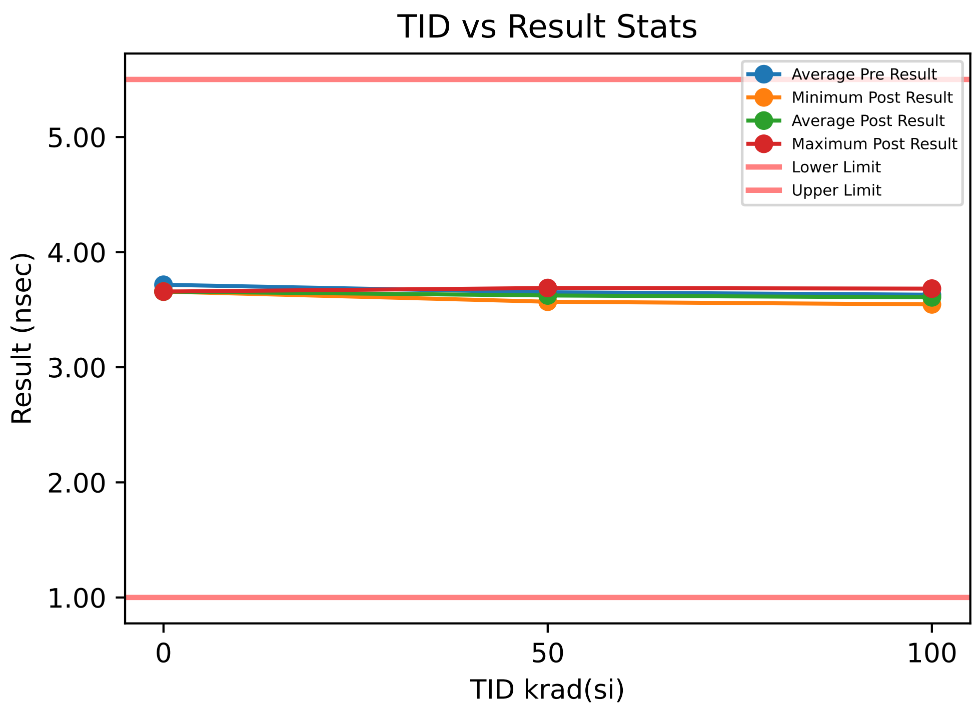
Test Results (Lower Limit = 1.0, Upper Limit = 7.5 (nsec))

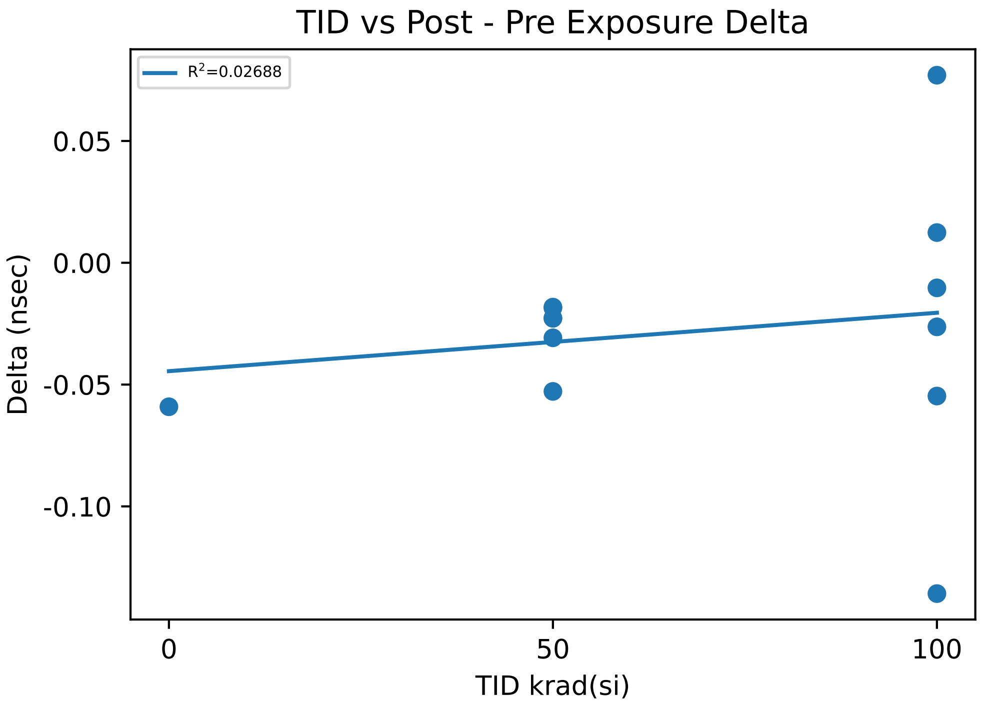
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.5021	3.7561	0.254
60	50	Biased	3.6538	3.5258	-0.128
61	50	Biased	3.5058	3.7668	0.261
63	100	Biased	3.5033	3.7609	0.2576
64	100	Biased	3.6564	3.7577	0.1013
65	100	Biased	3.5066	3.519	0.0124
66	50	Unbiased	3.6555	3.5342	-0.1213
67	50	Unbiased	3.5011	3.7691	0.268
68	50	Unbiased	3.6525	3.5195	-0.133
69	100	Unbiased	3.4976	3.7668	0.2692
70	100	Unbiased	3.656	3.5145	-0.1415
71	100	Unbiased	3.4924	3.7453	0.2529
72	0	Control	3.6576	3.5036	-0.154

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6576	3.6576	3.6576		3.5036	3.5036	3.5036		-0.154	-0.154	-0.154	
50	3.5011	3.5785	3.6555	0.08269	3.5195	3.6452	3.7691	0.13024	-0.133	0.066783	0.268	0.21283
100	3.4924	3.552	3.6564	0.08082	3.5145	3.6774	3.7668	0.12462	-0.1415	0.12532	0.2692	0.16673

Device Test: 117.1 Fall Time HO VIN_14V





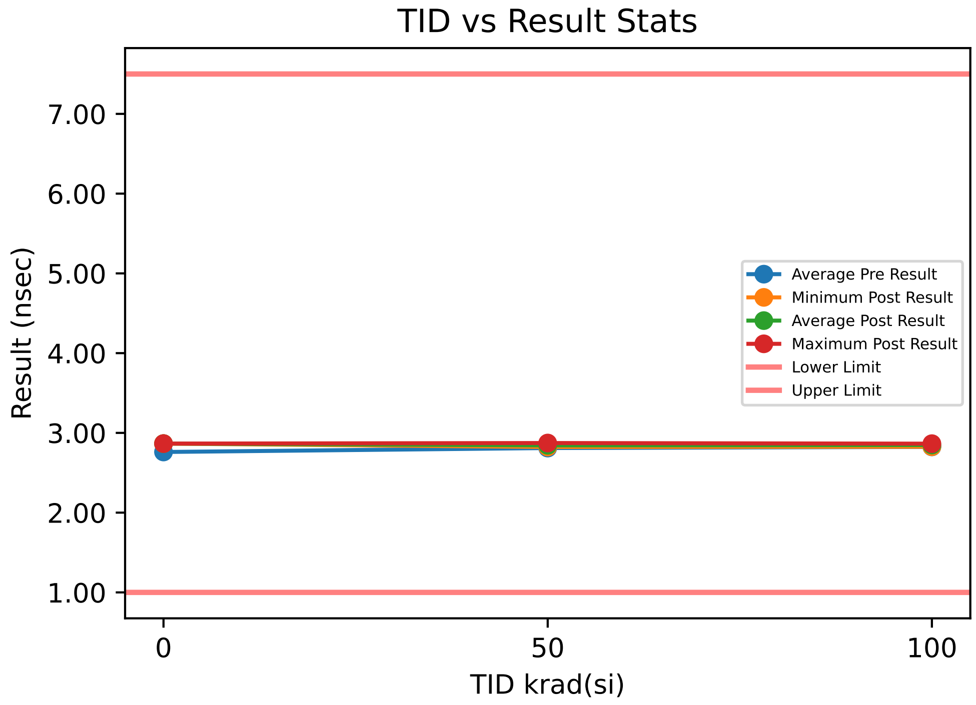
Test Results (Lower Limit = 1.0, Upper Limit = 5.5 (nsec))

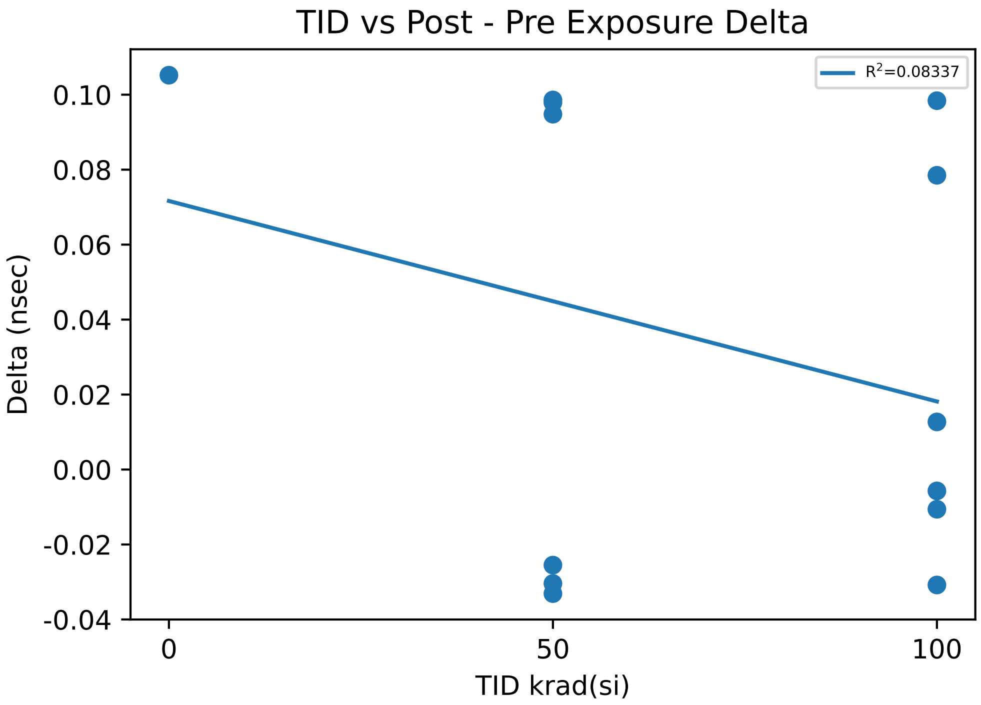
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.603	3.5848	-0.0182
60	50	Biased	3.6926	3.6618	-0.0308
61	50	Biased	3.6044	3.5816	-0.0228
63	100	Biased	3.6025	3.5762	-0.0263
64	100	Biased	3.701	3.5652	-0.1358
65	100	Biased	3.5923	3.6693	0.077
66	50	Unbiased	3.7068	3.6883	-0.0185
67	50	Unbiased	3.6219	3.5691	-0.0528
68	50	Unbiased	3.6779	3.6552	-0.0227
69	100	Unbiased	3.5909	3.6033	0.0124
70	100	Unbiased	3.6932	3.6829	-0.0103
71	100	Unbiased	3.6007	3.546	-0.0547
72	0	Control	3.7165	3.6574	-0.0591

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7165	3.7165	3.7165		3.6574	3.6574	3.6574		-0.0591	-0.0591	-0.0591	
50	3.603	3.6511	3.7068	0.046669	3.5691	3.6235	3.6883	0.050761	-0.0528	-0.027633	-0.0182	0.013141
100	3.5909	3.6301	3.701	0.052154	3.546	3.6072	3.6829	0.056697	-0.1358	-0.02295	0.077	0.070928

Device Test: 117.2 Rise Time LO VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

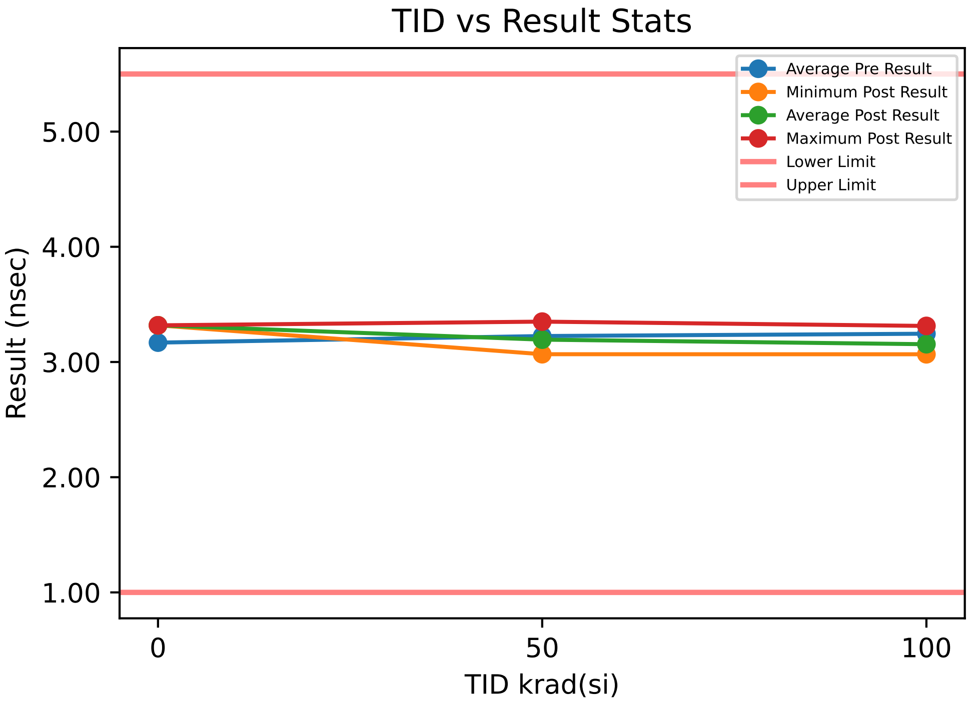
Test Results (Lower Limit = 1.0, Upper Limit = 7.5 (nsec))

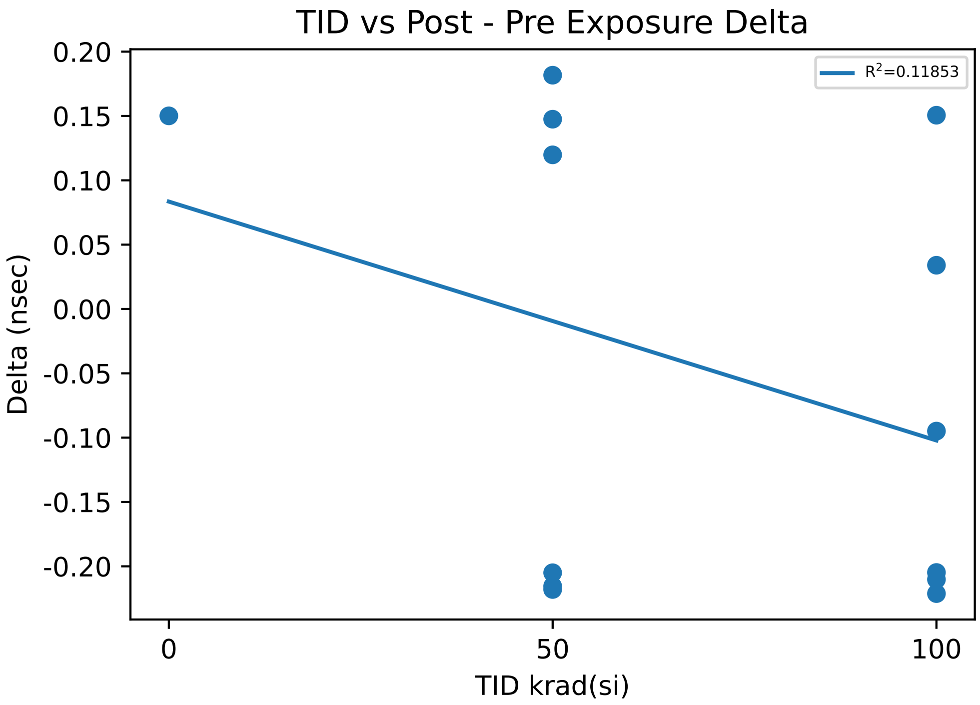
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.8533	2.8229	-0.0304
60	50	Biased	2.775	2.8729	0.0979
61	50	Biased	2.8582	2.8251	-0.0331
63	100	Biased	2.8571	2.8514	-0.0057
64	100	Biased	2.7602	2.8387	0.0785
65	100	Biased	2.8522	2.8649	0.0127
66	50	Unbiased	2.7655	2.8603	0.0948
67	50	Unbiased	2.8551	2.8296	-0.0255
68	50	Unbiased	2.7526	2.8512	0.0986
69	100	Unbiased	2.857	2.8262	-0.0308
70	100	Unbiased	2.7638	2.8622	0.0984
71	100	Unbiased	2.8568	2.8462	-0.0106
72	0	Control	2.7606	2.8658	0.1052

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7606	2.7606	2.7606		2.8658	2.8658	2.8658		0.1052	0.1052	0.1052	
50	2.7526	2.81	2.8582	0.050462	2.8229	2.8437	2.8729	0.020794	-0.0331	0.033717	0.0986	0.069487
100	2.7602	2.8245	2.8571	0.048474	2.8262	2.8483	2.8649	0.014583	-0.0308	0.02375	0.0984	0.052374

Device Test: 117.3 Fall Time LO VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

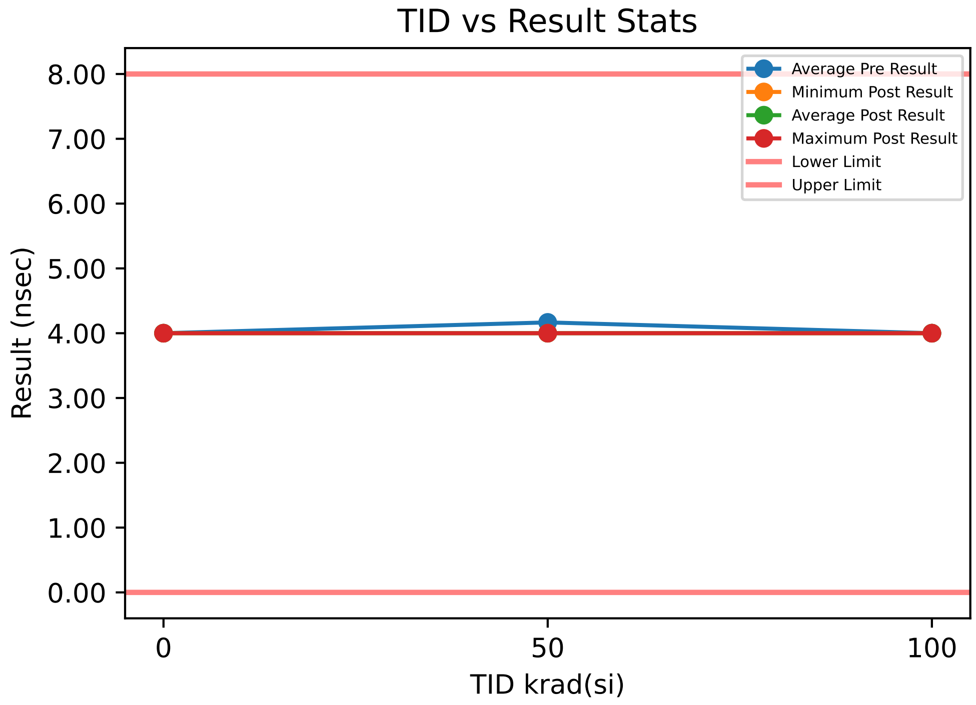
Test Results (Lower Limit = 1.0, Upper Limit = 5.5 (nsec))

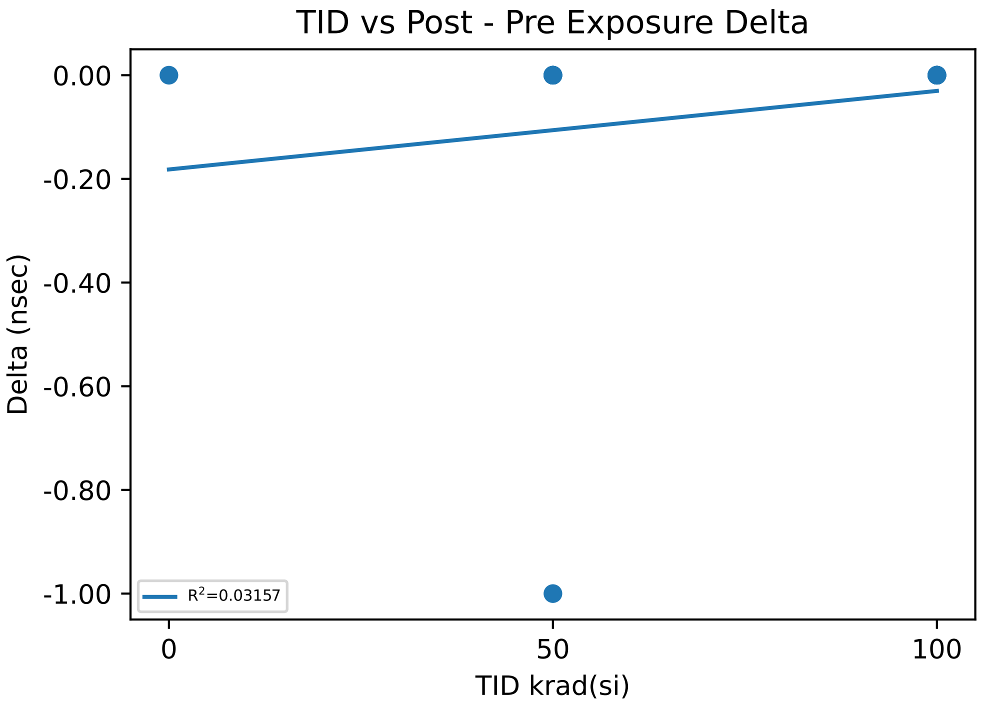
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.2759	3.0709	-0.205
60	50	Biased	3.1756	3.2954	0.1198
61	50	Biased	3.283	3.0676	-0.2154
63	100	Biased	3.2889	3.0787	-0.2102
64	100	Biased	3.164	3.0691	-0.0949
65	100	Biased	3.2708	3.3048	0.034
66	50	Unbiased	3.1687	3.3504	0.1817
67	50	Unbiased	3.2917	3.0737	-0.218
68	50	Unbiased	3.1581	3.3056	0.1475
69	100	Unbiased	3.2883	3.0671	-0.2212
70	100	Unbiased	3.1625	3.3131	0.1506
71	100	Unbiased	3.2981	3.0933	-0.2048
72	0	Control	3.1683	3.3184	0.1501

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.1683	3.1683	3.1683		3.3184	3.3184	3.3184		0.1501	0.1501	0.1501	
50	3.1581	3.2255	3.2917	0.064012	3.0676	3.1939	3.3504	0.13624	-0.218	-0.031567	0.1817	0.19954
100	3.1625	3.2454	3.2981	0.06427	3.0671	3.1544	3.3131	0.12014	-0.2212	-0.091083	0.1506	0.1537

Device Test: 120.0 Min Input PW Static HS Turn On VIN_10V





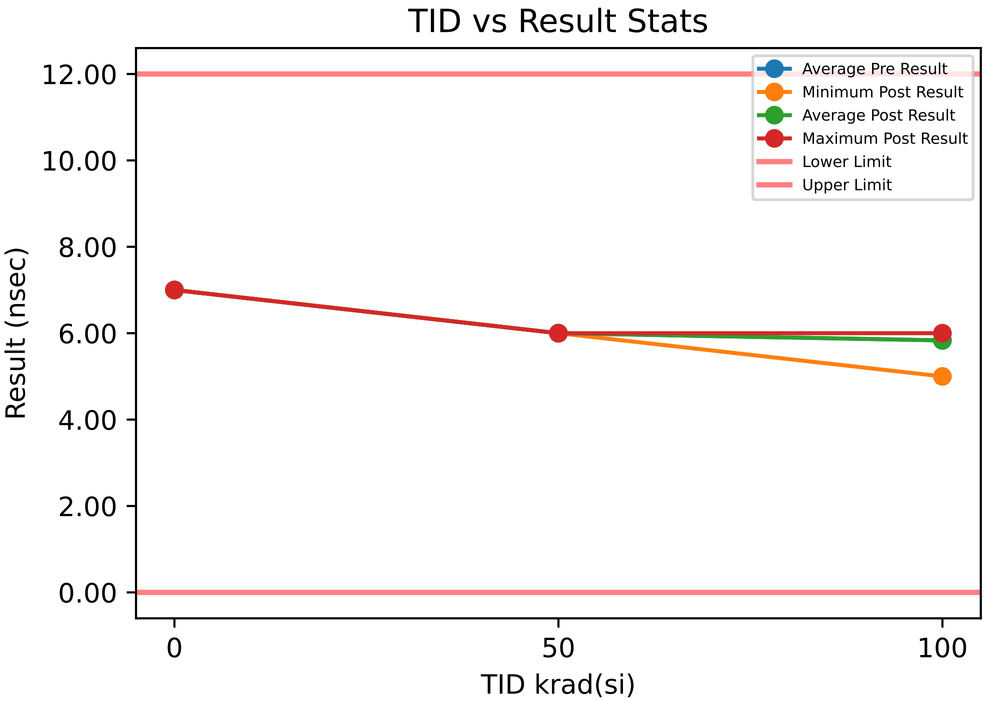
Test Results (Lower Limit = 0.0, Upper Limit = 8.0 (nsec))

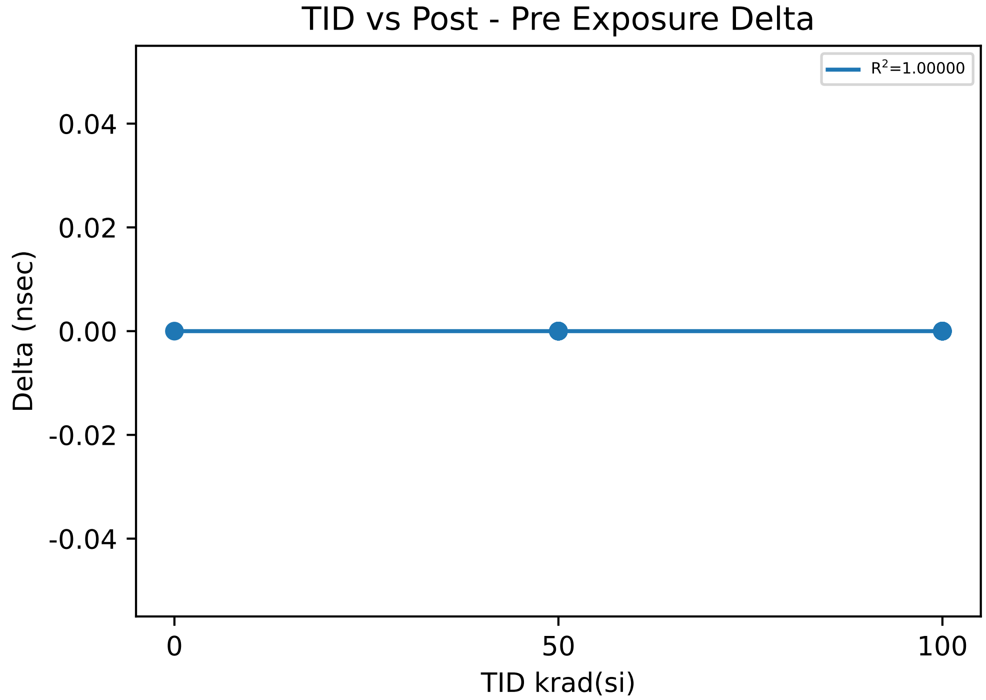
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4	4	0
60	50	Biased	4	4	0
61	50	Biased	5	4	-1
63	100	Biased	4	4	0
64	100	Biased	4	4	0
65	100	Biased	4	4	0
66	50	Unbiased	4	4	0
67	50	Unbiased	4	4	0
68	50	Unbiased	4	4	0
69	100	Unbiased	4	4	0
70	100	Unbiased	4	4	0
71	100	Unbiased	4	4	0
72	0	Control	4	4	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4	4	4		4	4	4		0	0	0	
50	4	4.1667	5	0.40825	4	4	4	0	-1	-0.16667	0	0.40825
100	4	4	4	0	4	4	4	0	0	0	0	0

Device Test: 120.1 Min Input PW Static HS Turn Off VIN_10V





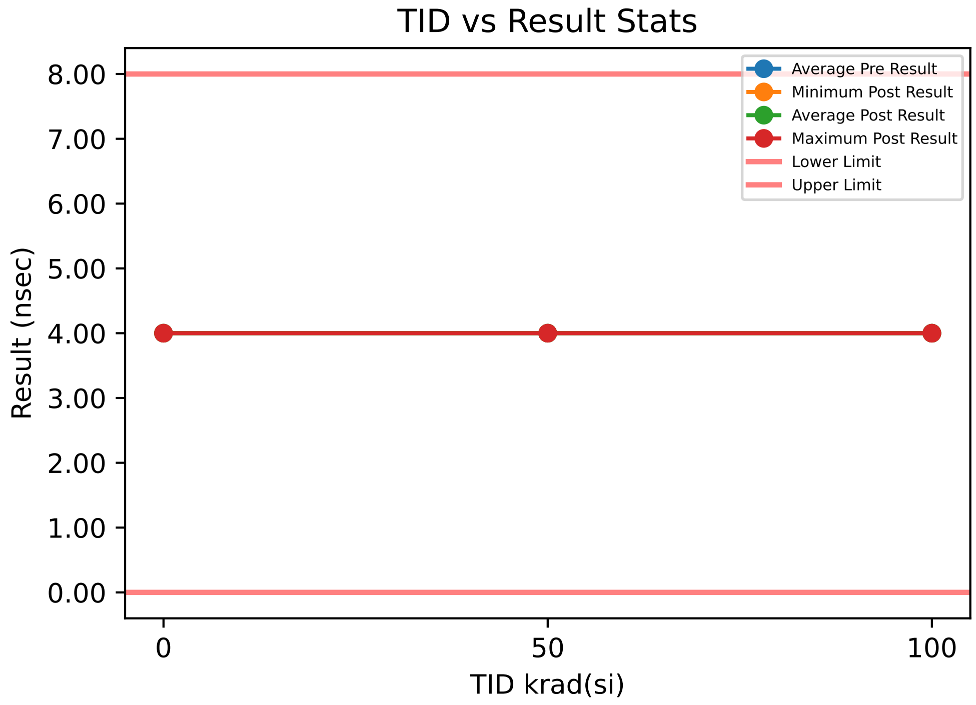
Test Results (Lower Limit = 0.0, Upper Limit = 12.0 (nsec))

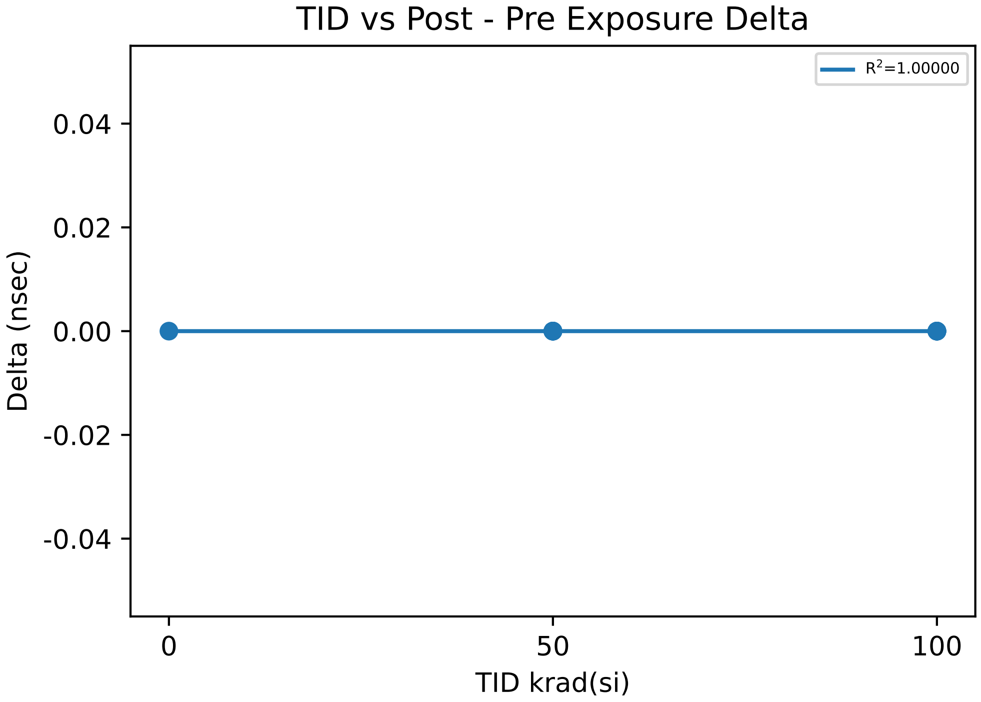
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6	6	0
60	50	Biased	6	6	0
61	50	Biased	6	6	0
63	100	Biased	6	6	0
64	100	Biased	6	6	0
65	100	Biased	5	5	0
66	50	Unbiased	6	6	0
67	50	Unbiased	6	6	0
68	50	Unbiased	6	6	0
69	100	Unbiased	6	6	0
70	100	Unbiased	6	6	0
71	100	Unbiased	6	6	0
72	0	Control	7	7	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7	7	7		7	7	7		0	0	0	
50	6	6	6	0	6	6	6	0	0	0	0	0
100	5	5.8333	6	0.40825	5	5.8333	6	0.40825	0	0	0	0

Device Test: 120.2 Min Input PW Static LS Turn On VIN_10V





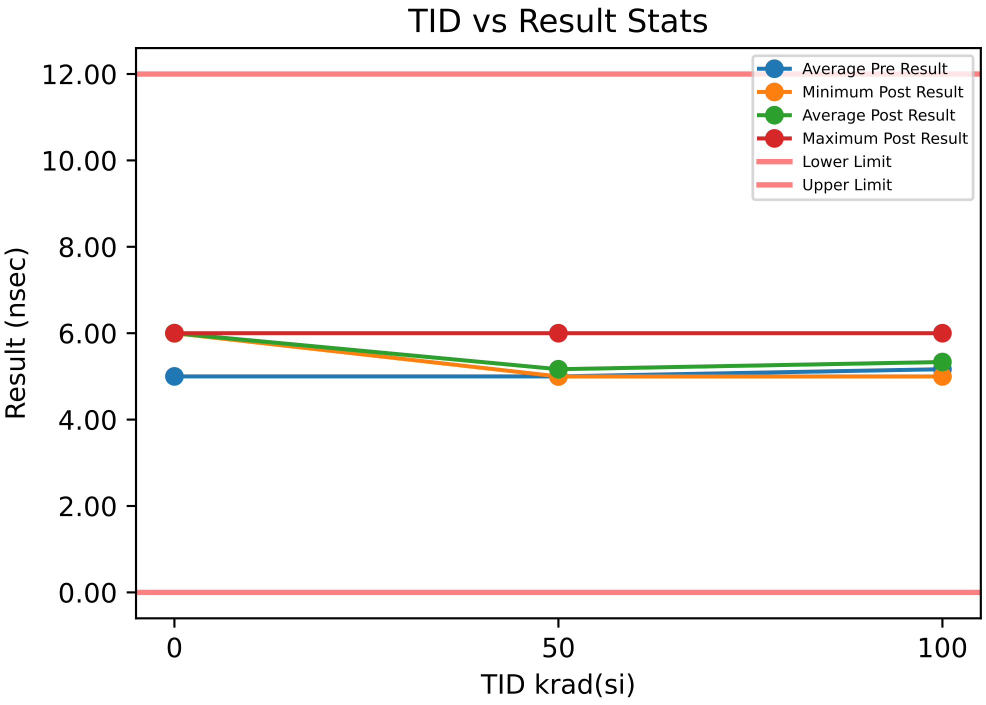
Test Results (Lower Limit = 0.0, Upper Limit = 8.0 (nsec))

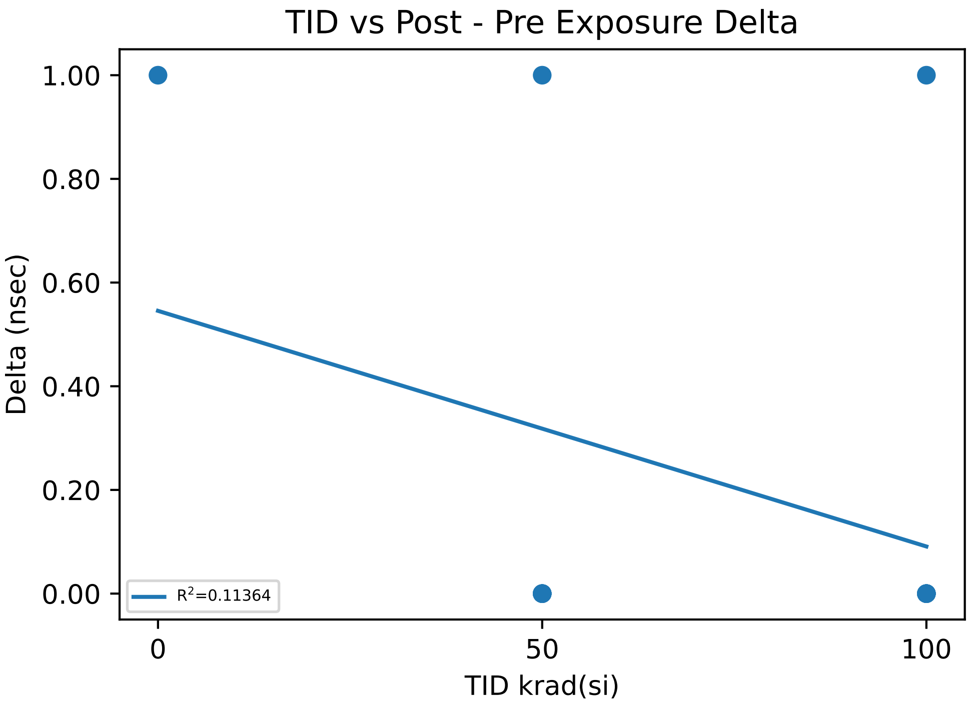
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4	4	0
60	50	Biased	4	4	0
61	50	Biased	4	4	0
63	100	Biased	4	4	0
64	100	Biased	4	4	0
65	100	Biased	4	4	0
66	50	Unbiased	4	4	0
67	50	Unbiased	4	4	0
68	50	Unbiased	4	4	0
69	100	Unbiased	4	4	0
70	100	Unbiased	4	4	0
71	100	Unbiased	4	4	0
72	0	Control	4	4	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4	4	4		4	4	4		0	0	0	
50	4	4	4	0	4	4	4	0	0	0	0	0
100	4	4	4	0	4	4	4	0	0	0	0	0

Device Test: 120.3 Min Input PW Static LS Turn Off VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

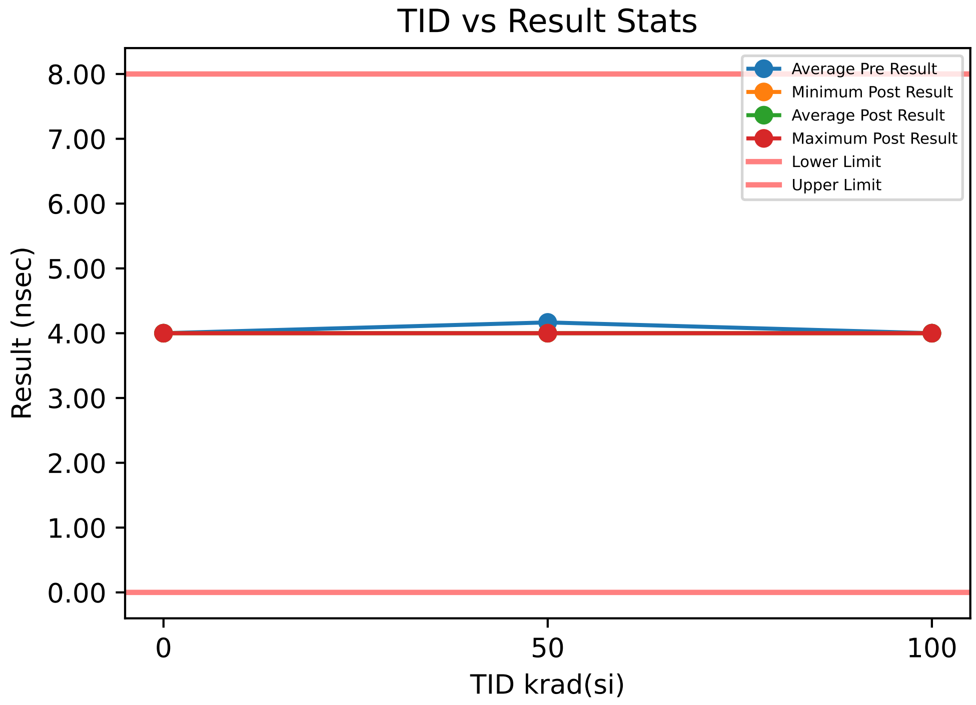
Test Results (Lower Limit = 0.0, Upper Limit = 12.0 (nsec))

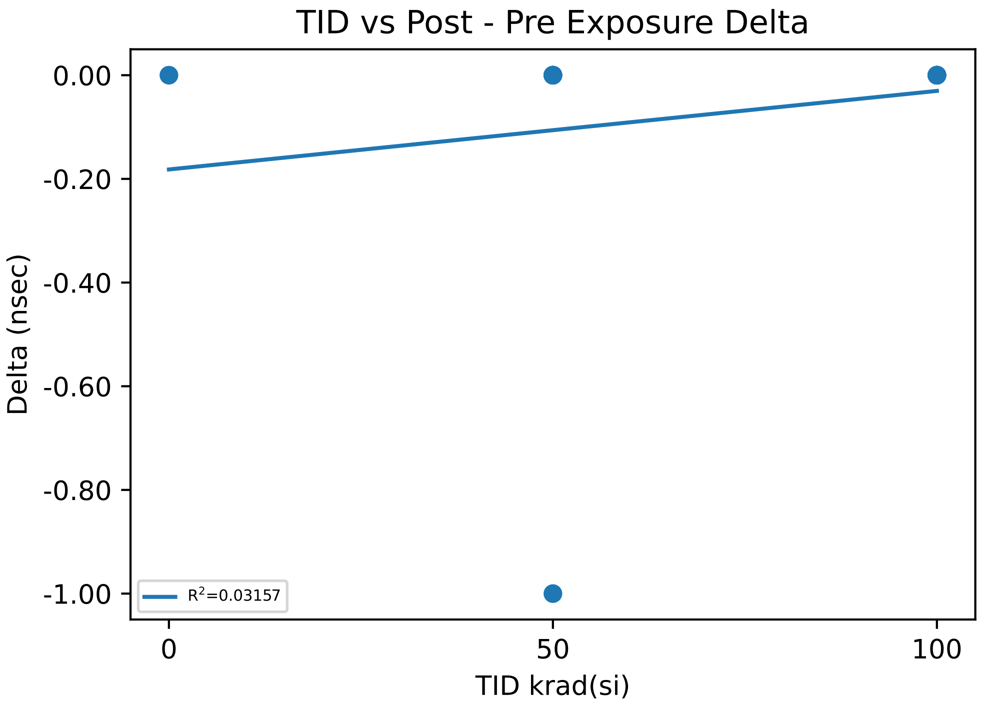
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5	5	0
60	50	Biased	5	6	1
61	50	Biased	5	5	0
63	100	Biased	5	5	0
64	100	Biased	6	6	0
65	100	Biased	5	5	0
66	50	Unbiased	5	5	0
67	50	Unbiased	5	5	0
68	50	Unbiased	5	5	0
69	100	Unbiased	5	5	0
70	100	Unbiased	5	6	1
71	100	Unbiased	5	5	0
72	0	Control	5	6	1

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5		6	6	6		1	1	1	
50	5	5	5	0	5	5.1667	6	0.40825	0	0.16667	1	0.40825
100	5	5.1667	6	0.40825	5	5.3333	6	0.5164	0	0.16667	1	0.40825

Device Test: 120.4 Min Input PW Static HS Turn On SW=100V VIN_10V





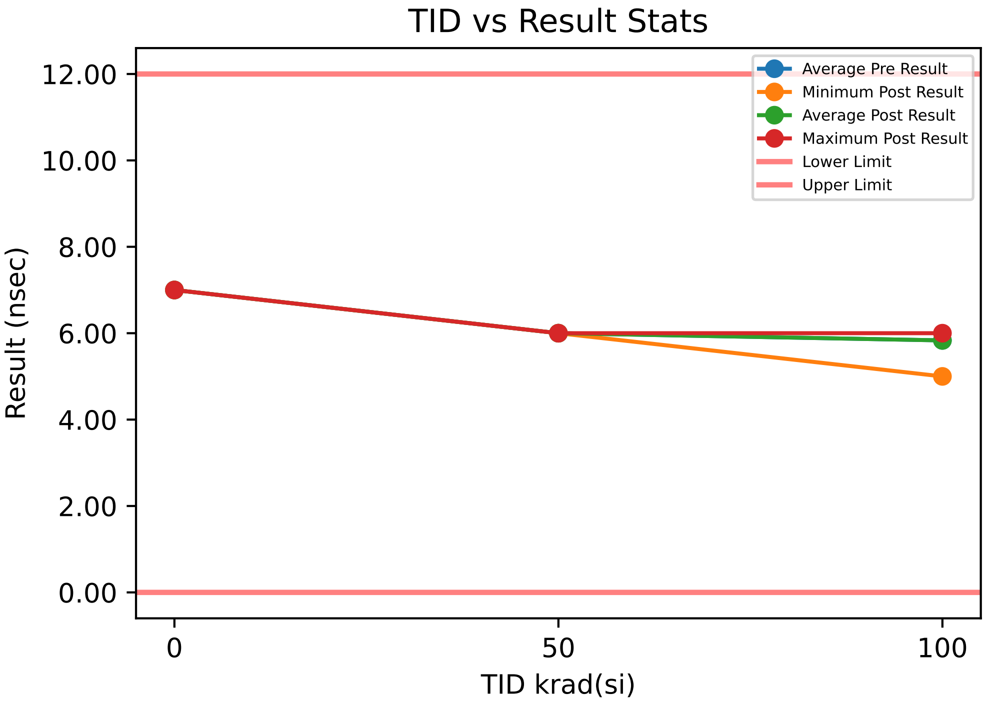
Test Results (Lower Limit = 0.0, Upper Limit = 8.0 (nsec))

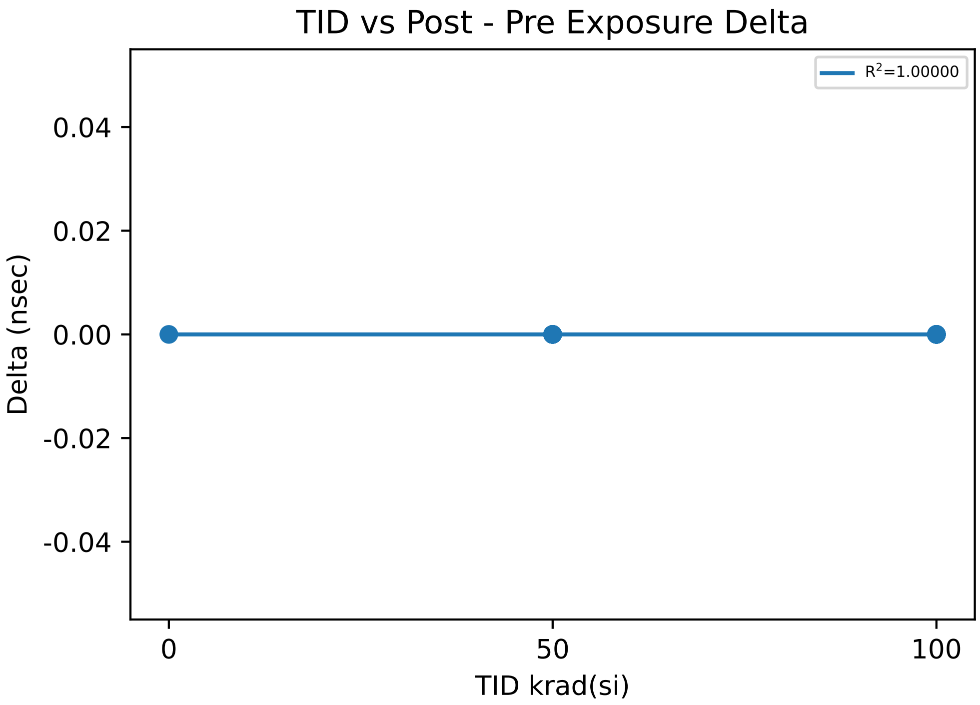
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4	4	0
60	50	Biased	4	4	0
61	50	Biased	5	4	-1
63	100	Biased	4	4	0
64	100	Biased	4	4	0
65	100	Biased	4	4	0
66	50	Unbiased	4	4	0
67	50	Unbiased	4	4	0
68	50	Unbiased	4	4	0
69	100	Unbiased	4	4	0
70	100	Unbiased	4	4	0
71	100	Unbiased	4	4	0
72	0	Control	4	4	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4	4	4		4	4	4		0	0	0	
50	4	4.1667	5	0.40825	4	4	4	0	-1	-0.16667	0	0.40825
100	4	4	4	0	4	4	4	0	0	0	0	0

Device Test: 120.5 Min Input PW Static HS Turn Off SW=100V VIN_10V





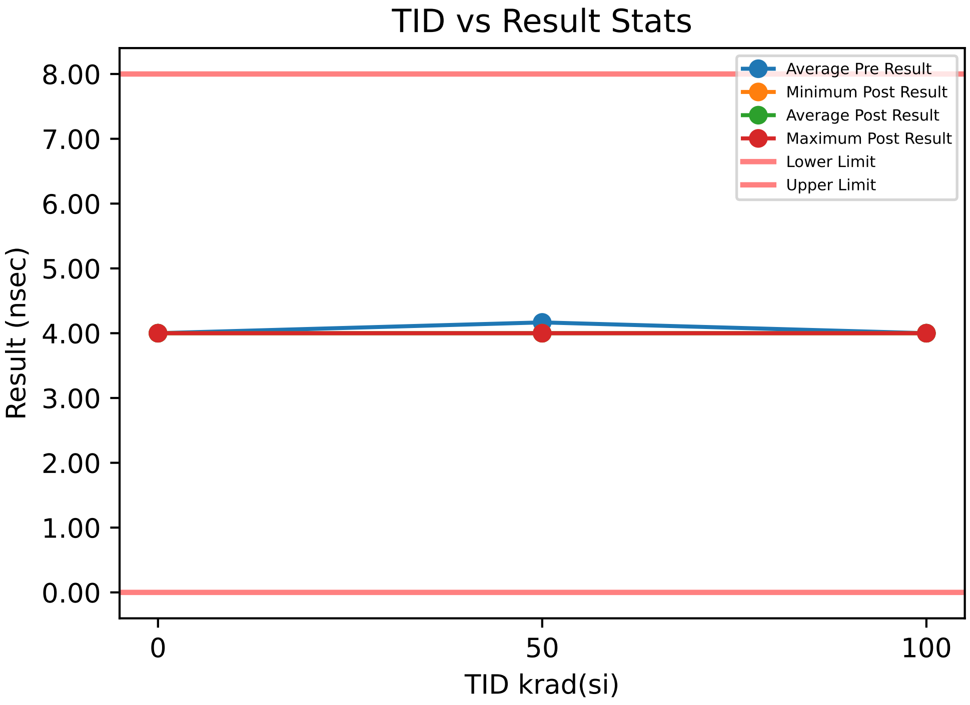
Test Results (Lower Limit = 0.0, Upper Limit = 12.0 (nsec))

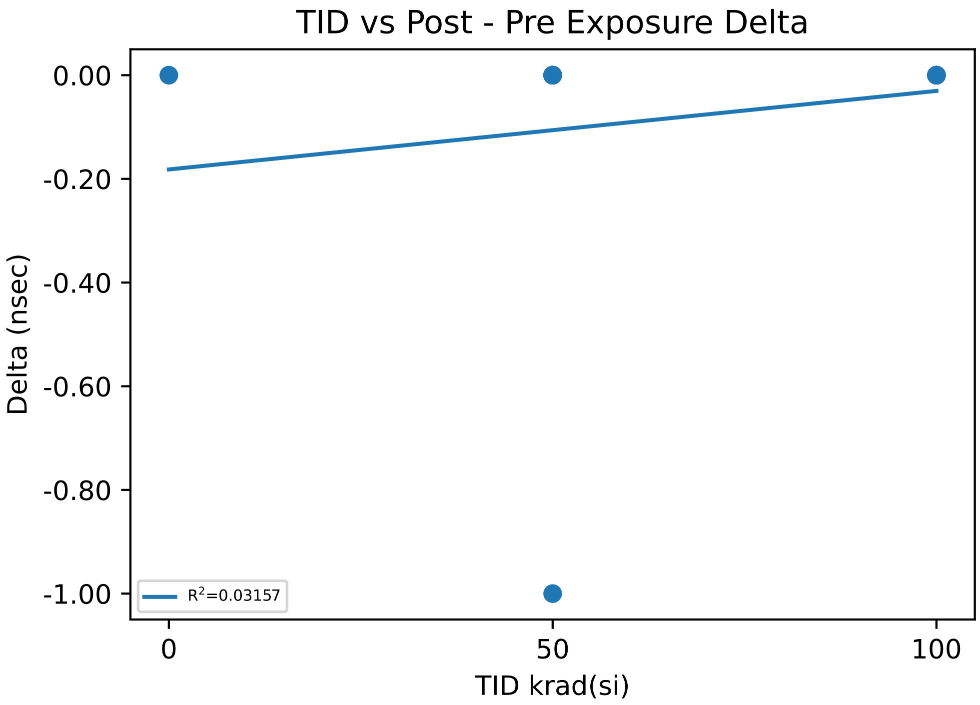
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6	6	0
60	50	Biased	6	6	0
61	50	Biased	6	6	0
63	100	Biased	6	6	0
64	100	Biased	6	6	0
65	100	Biased	5	5	0
66	50	Unbiased	6	6	0
67	50	Unbiased	6	6	0
68	50	Unbiased	6	6	0
69	100	Unbiased	6	6	0
70	100	Unbiased	6	6	0
71	100	Unbiased	6	6	0
72	0	Control	7	7	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7	7	7		7	7	7		0	0	0	
50	6	6	6	0	6	6	6	0	0	0	0	0
100	5	5.8333	6	0.40825	5	5.8333	6	0.40825	0	0	0	0

Device Test: 121.0 Min Input PW Static HS Turn On VIN_12V





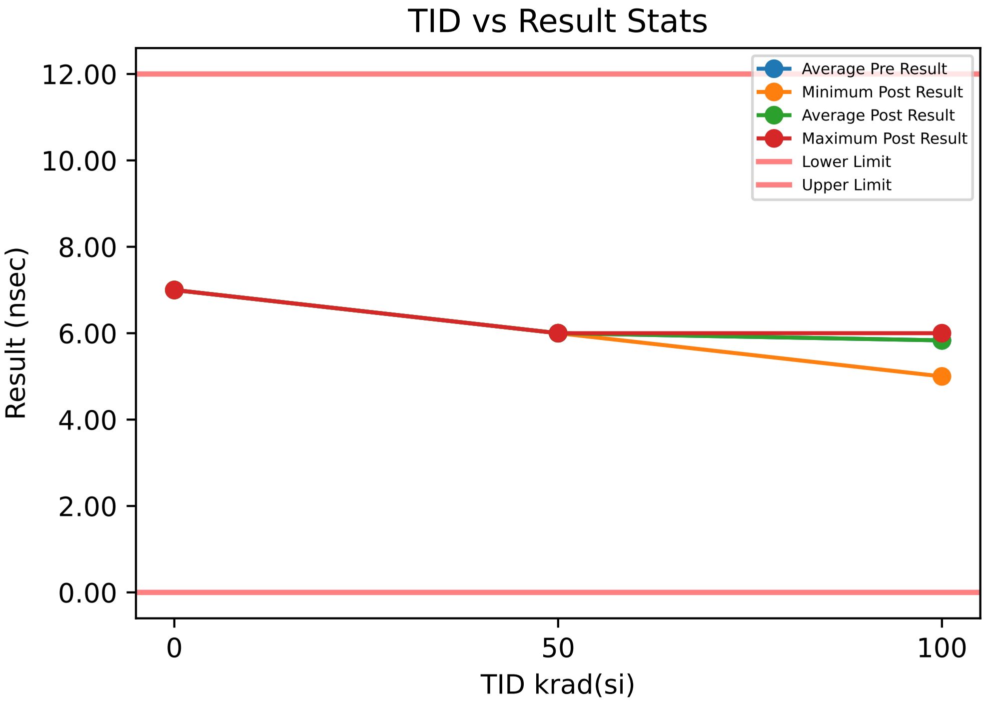
Test Results (Lower Limit = 0.0, Upper Limit = 8.0 (nsec))

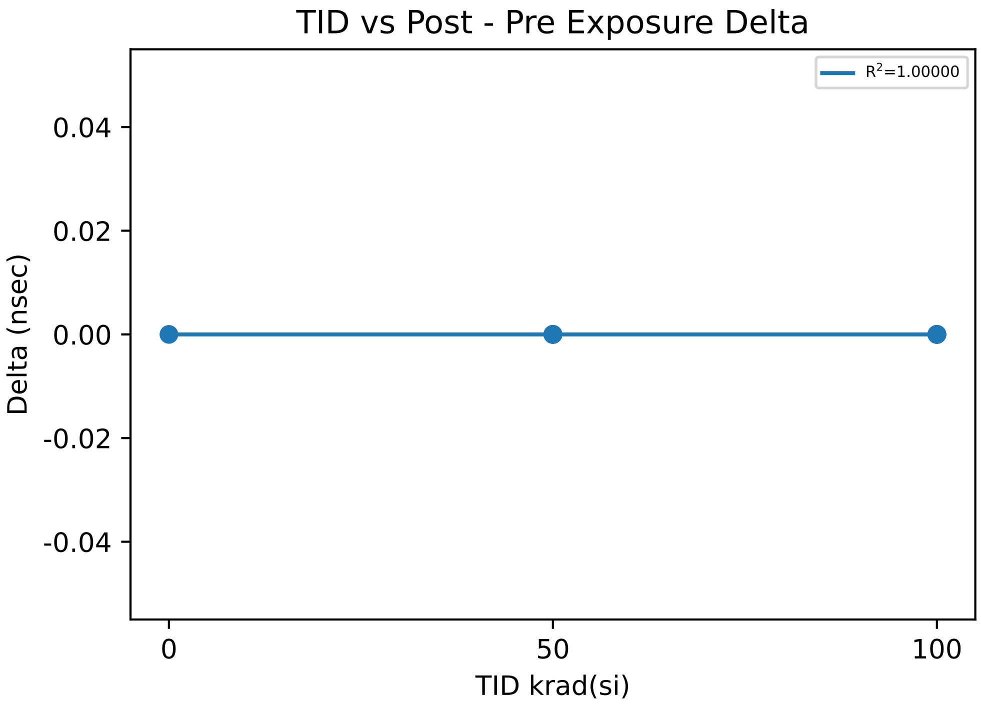
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4	4	0
60	50	Biased	4	4	0
61	50	Biased	5	4	-1
63	100	Biased	4	4	0
64	100	Biased	4	4	0
65	100	Biased	4	4	0
66	50	Unbiased	4	4	0
67	50	Unbiased	4	4	0
68	50	Unbiased	4	4	0
69	100	Unbiased	4	4	0
70	100	Unbiased	4	4	0
71	100	Unbiased	4	4	0
72	0	Control	4	4	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4	4	4		4	4	4		0	0	0	
50	4	4.1667	5	0.40825	4	4	4	0	-1	-0.16667	0	0.40825
100	4	4	4	0	4	4	4	0	0	0	0	0

Device Test: 121.1 Min Input PW Static HS Turn Off VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

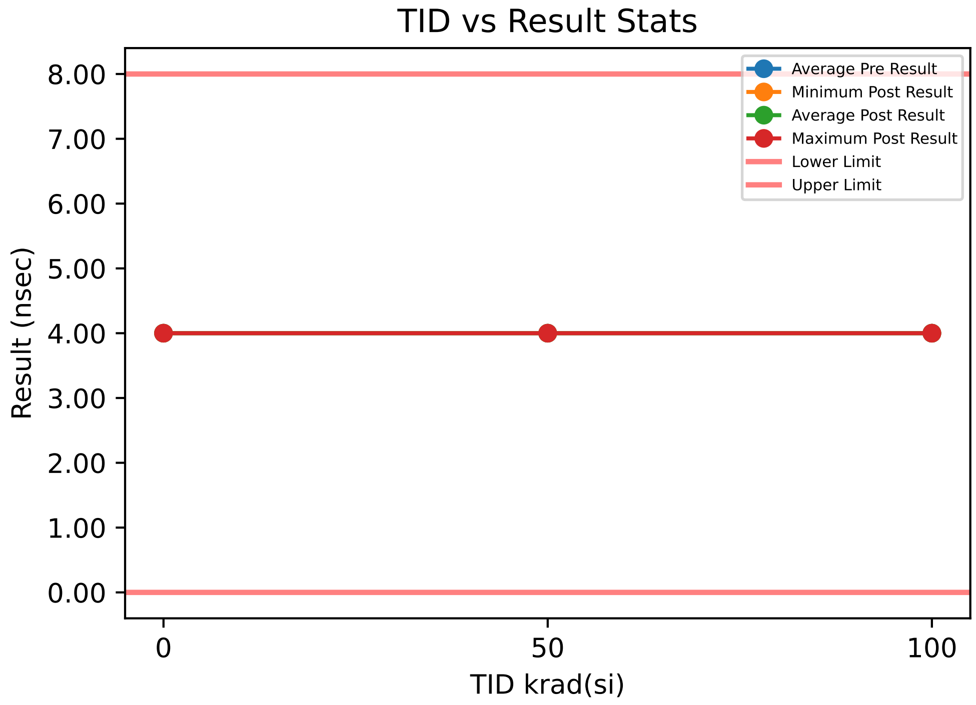
Test Results (Lower Limit = 0.0, Upper Limit = 12.0 (nsec))

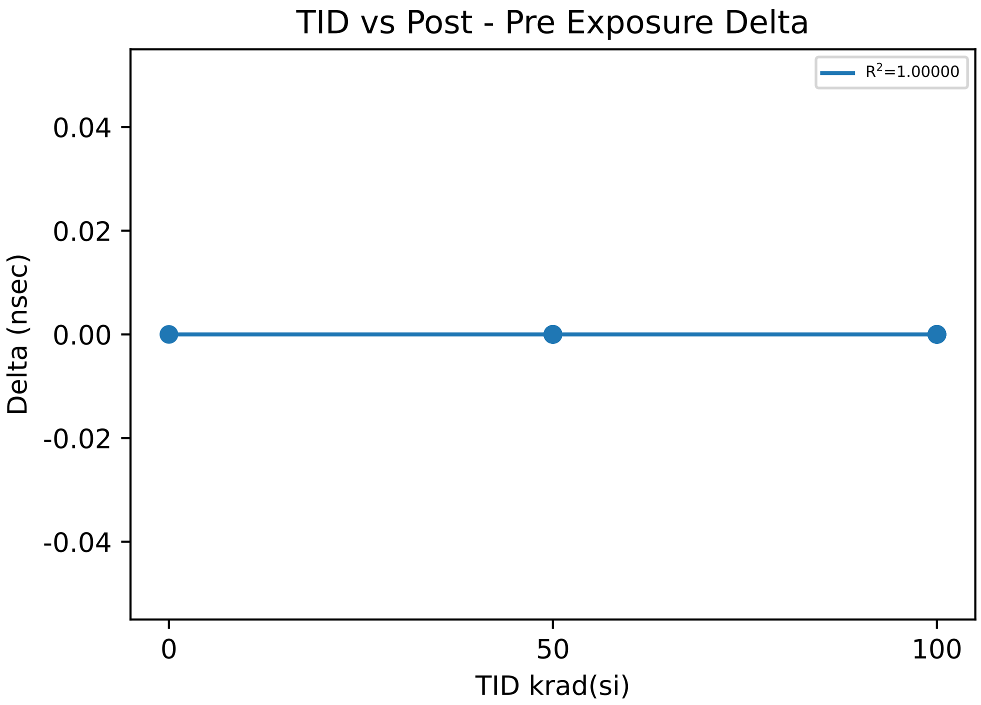
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6	6	0
60	50	Biased	6	6	0
61	50	Biased	6	6	0
63	100	Biased	6	6	0
64	100	Biased	6	6	0
65	100	Biased	5	5	0
66	50	Unbiased	6	6	0
67	50	Unbiased	6	6	0
68	50	Unbiased	6	6	0
69	100	Unbiased	6	6	0
70	100	Unbiased	6	6	0
71	100	Unbiased	6	6	0
72	0	Control	7	7	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7	7	7		7	7	7		0	0	0	
50	6	6	6	0	6	6	6	0	0	0	0	0
100	5	5.8333	6	0.40825	5	5.8333	6	0.40825	0	0	0	0

Device Test: 121.2 Min Input PW Static LS Turn On VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

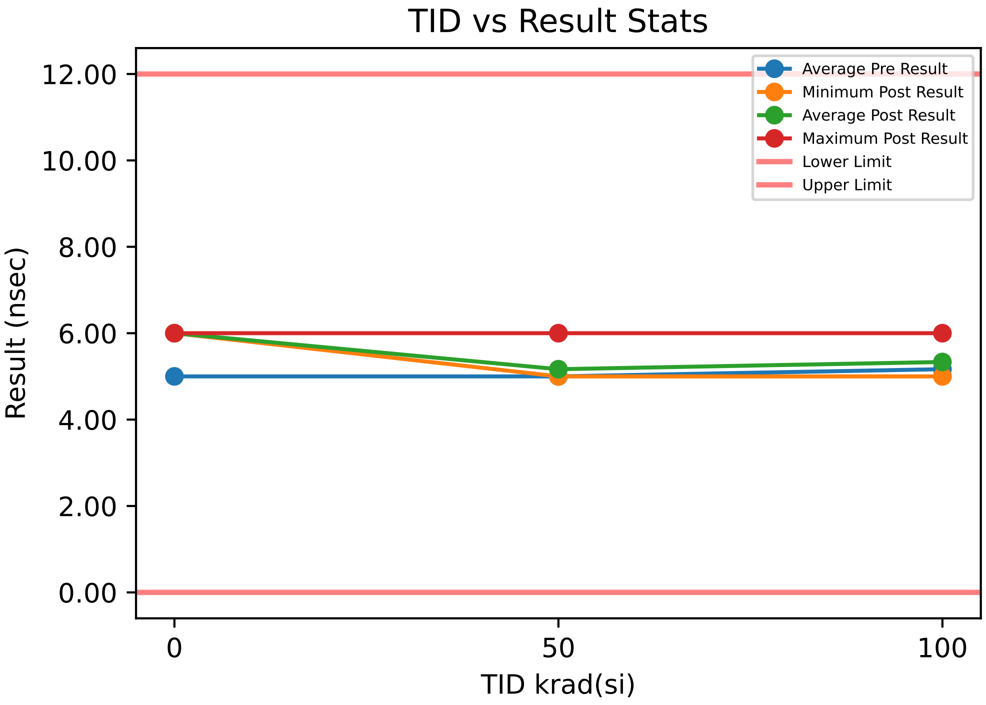
Test Results (Lower Limit = 0.0, Upper Limit = 8.0 (nsec))

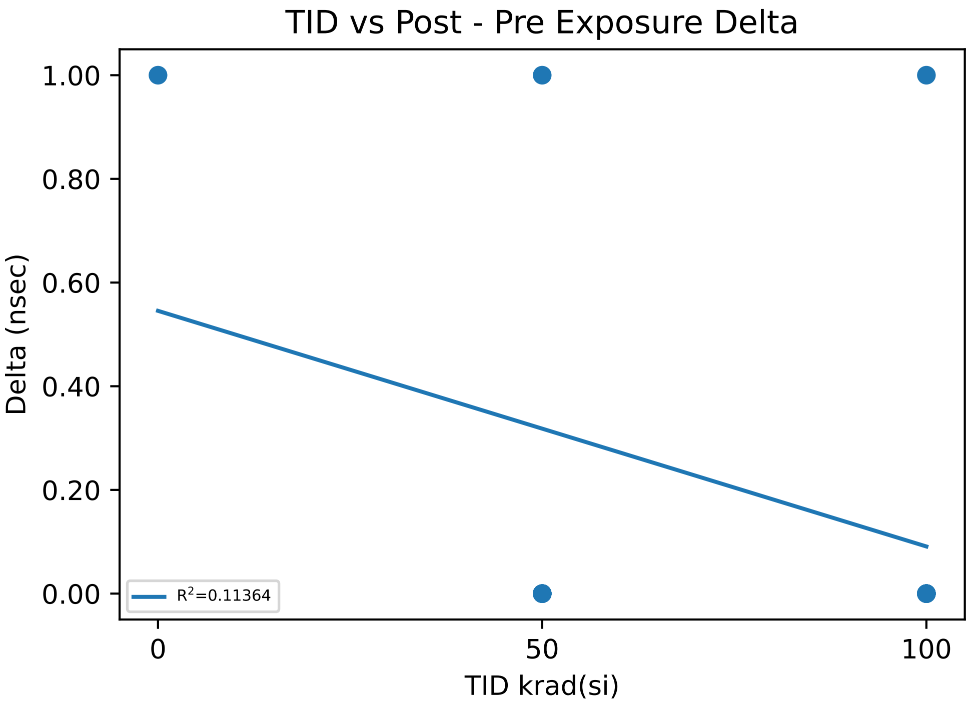
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4	4	0
60	50	Biased	4	4	0
61	50	Biased	4	4	0
63	100	Biased	4	4	0
64	100	Biased	4	4	0
65	100	Biased	4	4	0
66	50	Unbiased	4	4	0
67	50	Unbiased	4	4	0
68	50	Unbiased	4	4	0
69	100	Unbiased	4	4	0
70	100	Unbiased	4	4	0
71	100	Unbiased	4	4	0
72	0	Control	4	4	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4	4	4		4	4	4		0	0	0	
50	4	4	4	0	4	4	4	0	0	0	0	0
100	4	4	4	0	4	4	4	0	0	0	0	0

Device Test: 121.3 Min Input PW Static LS Turn Off VIN_12V





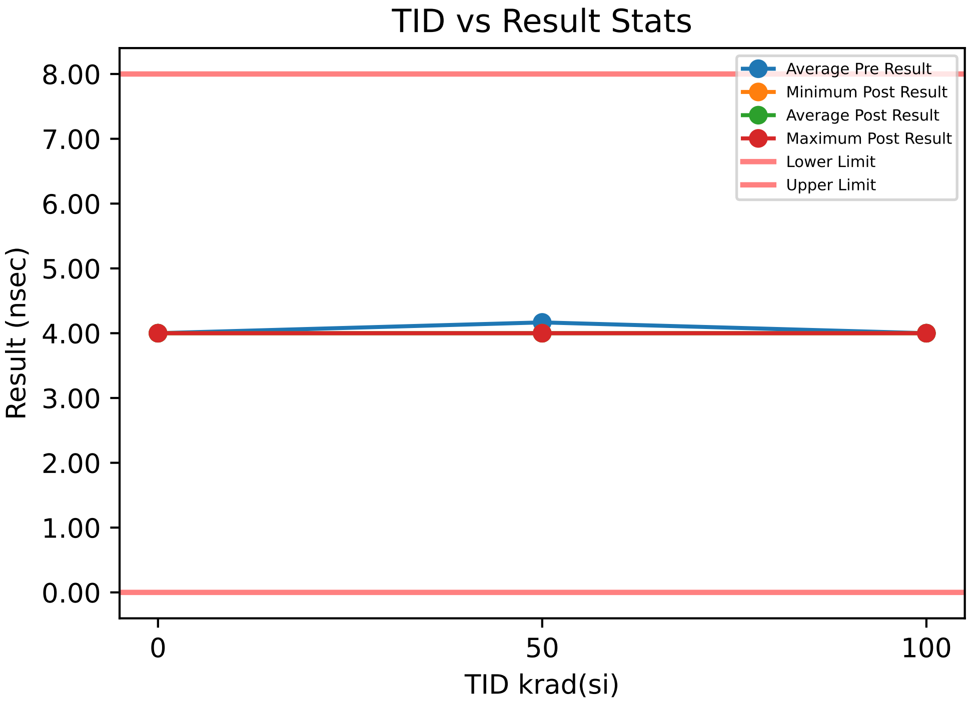
Test Results (Lower Limit = 0.0, Upper Limit = 12.0 (nsec))

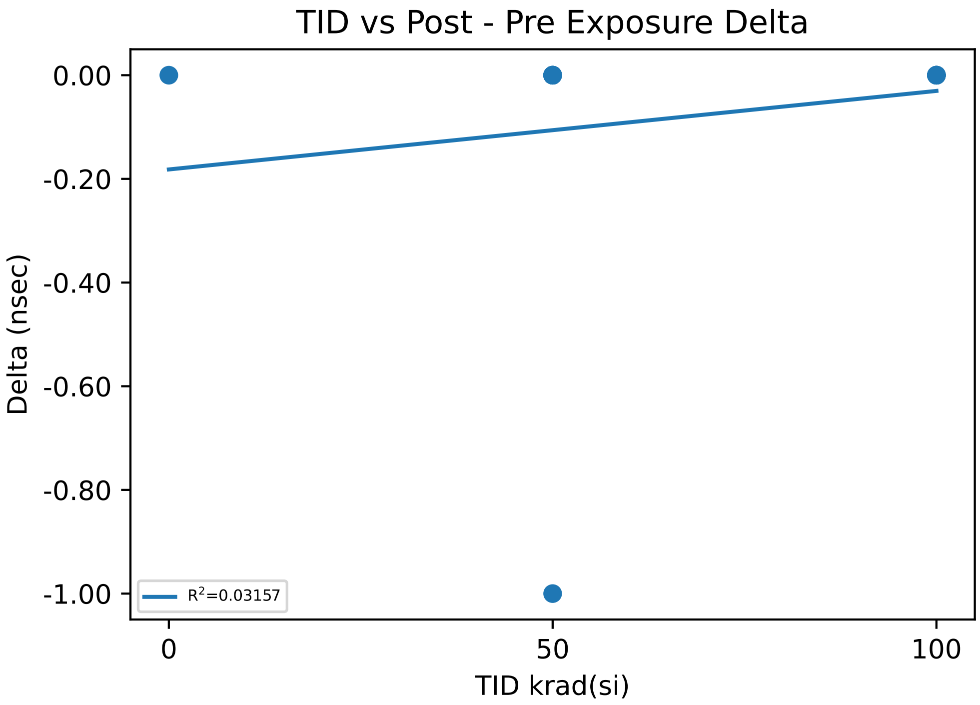
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5	5	0
60	50	Biased	5	6	1
61	50	Biased	5	5	0
63	100	Biased	5	5	0
64	100	Biased	6	6	0
65	100	Biased	5	5	0
66	50	Unbiased	5	5	0
67	50	Unbiased	5	5	0
68	50	Unbiased	5	5	0
69	100	Unbiased	5	5	0
70	100	Unbiased	5	6	1
71	100	Unbiased	5	5	0
72	0	Control	5	6	1

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5		6	6	6		1	1	1	
50	5	5	5	0	5	5.1667	6	0.40825	0	0.16667	1	0.40825
100	5	5.1667	6	0.40825	5	5.3333	6	0.5164	0	0.16667	1	0.40825

Device Test: 121.4 Min Input PW Static HS Turn On SW=100V VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

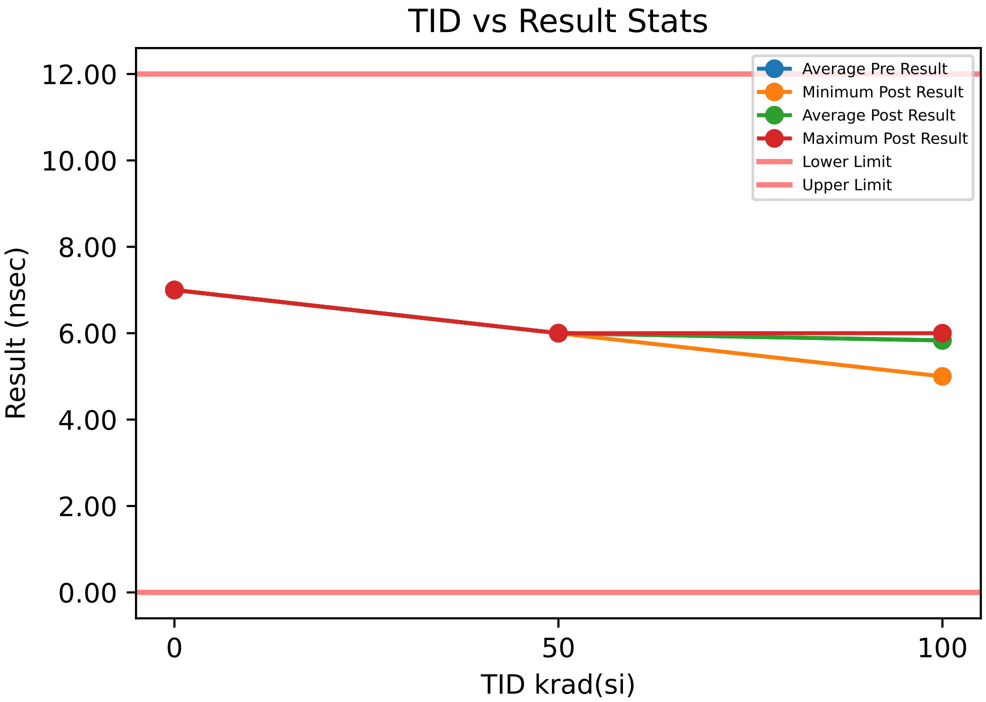
Test Results (Lower Limit = 0.0, Upper Limit = 8.0 (nsec))

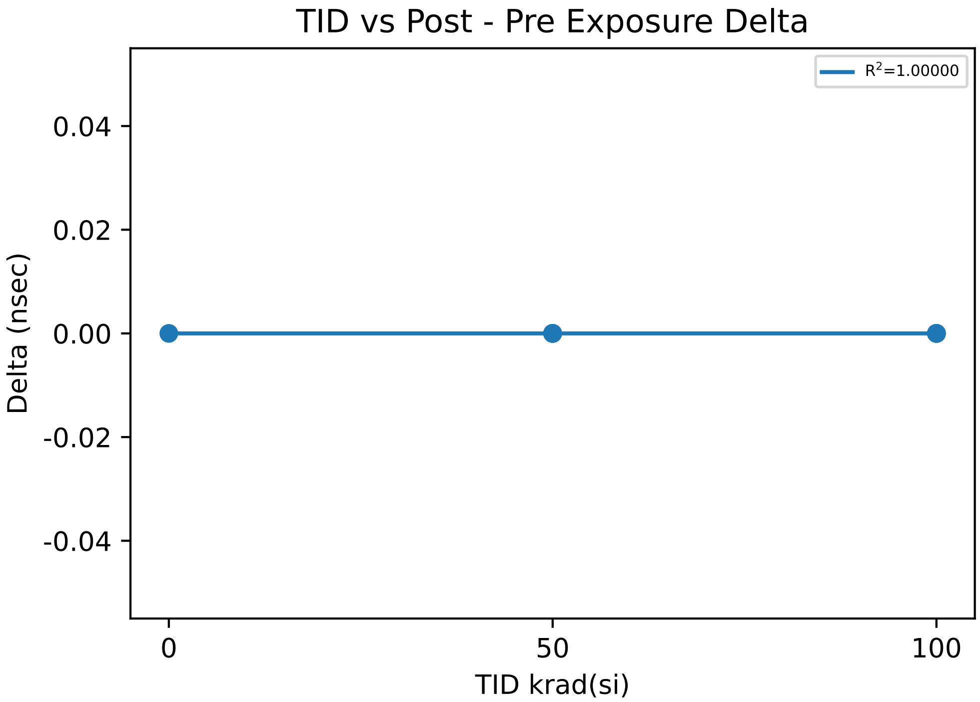
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4	4	0
60	50	Biased	4	4	0
61	50	Biased	5	4	-1
63	100	Biased	4	4	0
64	100	Biased	4	4	0
65	100	Biased	4	4	0
66	50	Unbiased	4	4	0
67	50	Unbiased	4	4	0
68	50	Unbiased	4	4	0
69	100	Unbiased	4	4	0
70	100	Unbiased	4	4	0
71	100	Unbiased	4	4	0
72	0	Control	4	4	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4	4	4		4	4	4		0	0	0	
50	4	4.1667	5	0.40825	4	4	4	0	-1	-0.16667	0	0.40825
100	4	4	4	0	4	4	4	0	0	0	0	0

Device Test: 121.5 Min Input PW Static HS Turn Off SW=100V VIN_12V





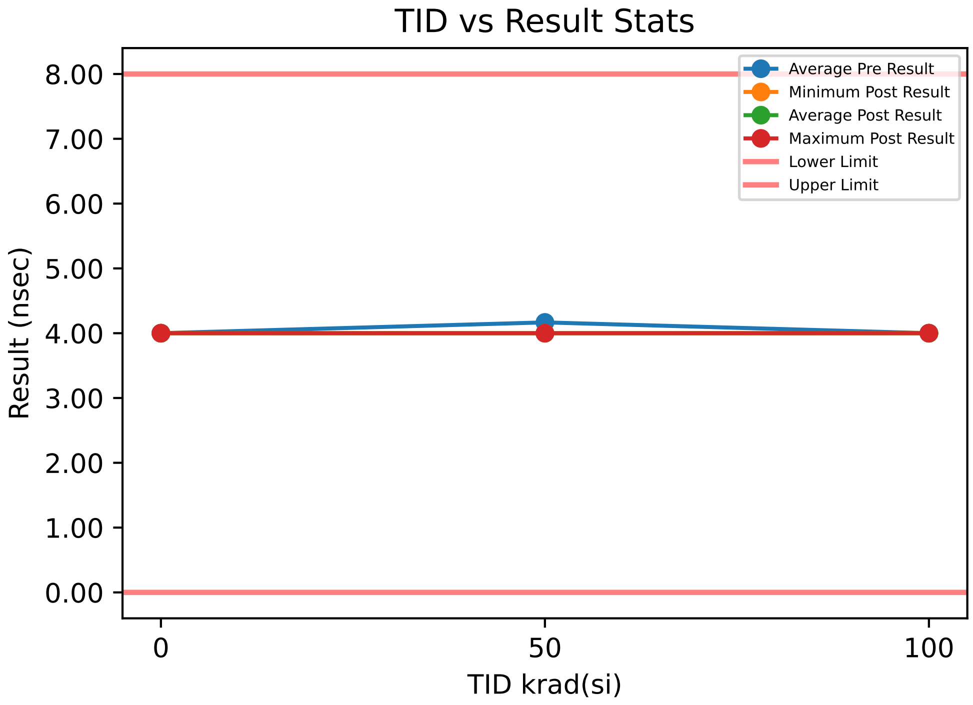
Test Results (Lower Limit = 0.0, Upper Limit = 12.0 (nsec))

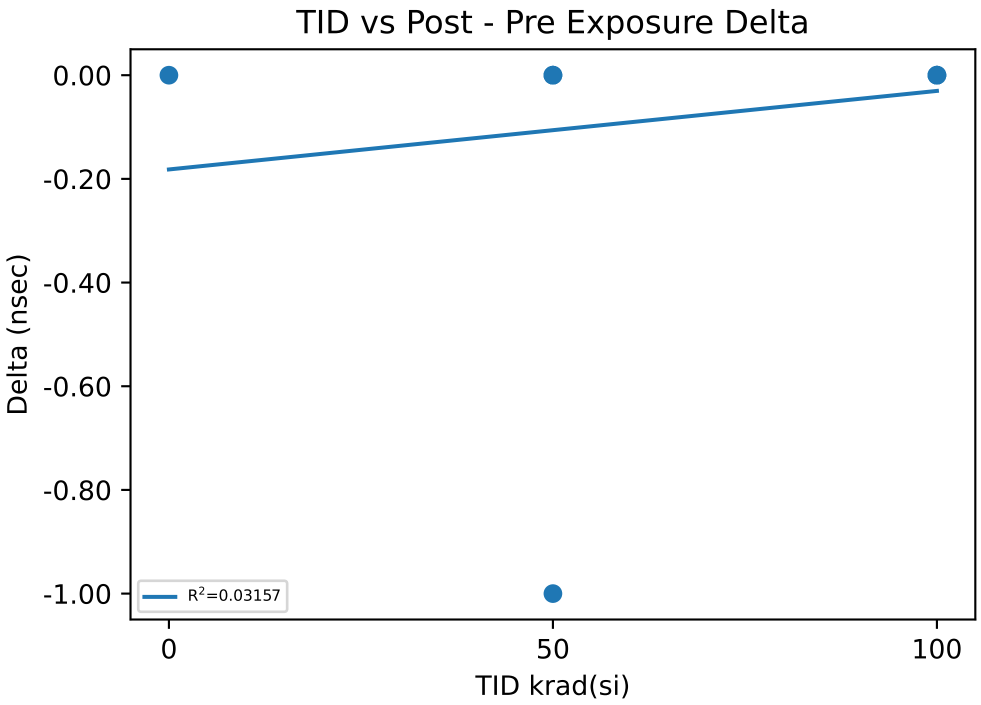
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6	6	0
60	50	Biased	6	6	0
61	50	Biased	6	6	0
63	100	Biased	6	6	0
64	100	Biased	6	6	0
65	100	Biased	5	5	0
66	50	Unbiased	6	6	0
67	50	Unbiased	6	6	0
68	50	Unbiased	6	6	0
69	100	Unbiased	6	6	0
70	100	Unbiased	6	6	0
71	100	Unbiased	6	6	0
72	0	Control	7	7	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7	7	7		7	7	7		0	0	0	
50	6	6	6	0	6	6	6	0	0	0	0	0
100	5	5.8333	6	0.40825	5	5.8333	6	0.40825	0	0	0	0

Device Test: 122.0 Min Input PW Static HS Turn On VIN_14V





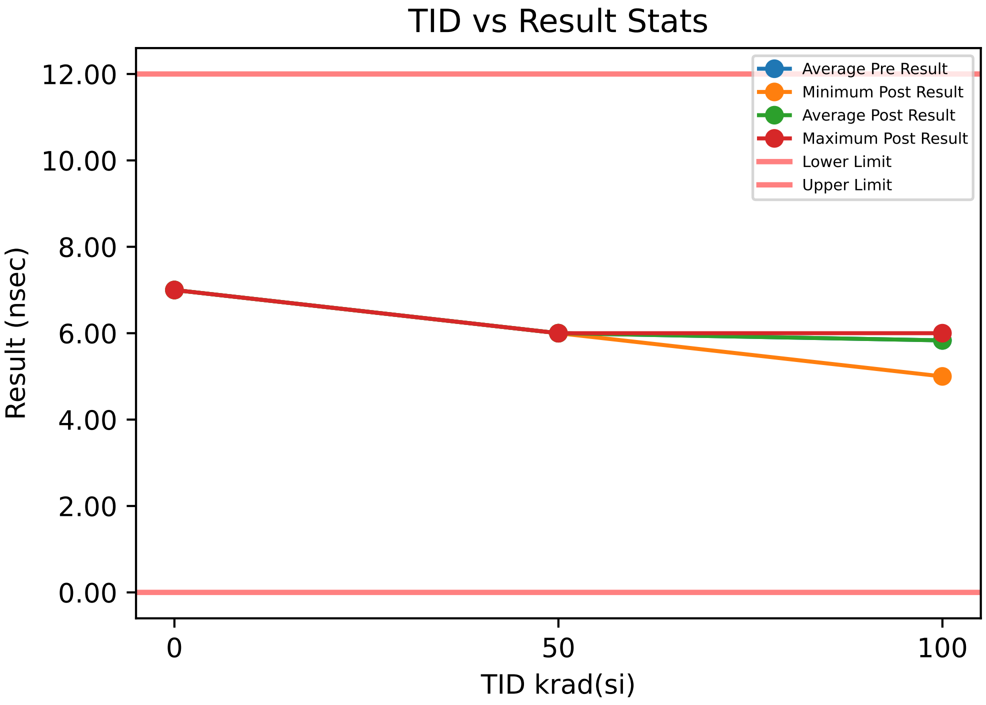
Test Results (Lower Limit = 0.0, Upper Limit = 8.0 (nsec))

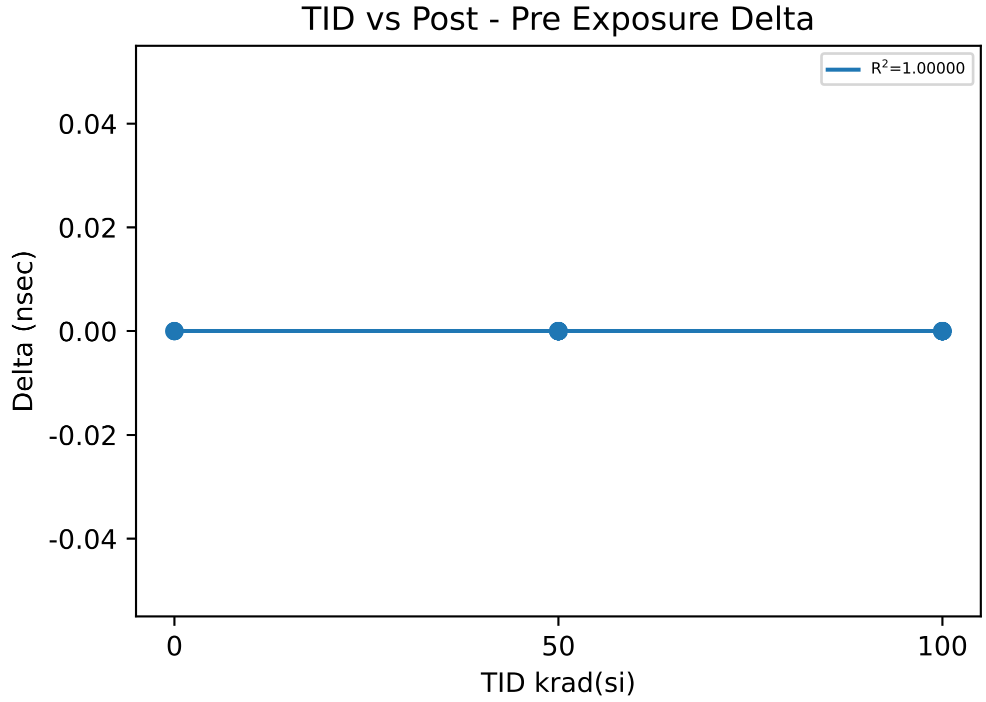
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4	4	0
60	50	Biased	4	4	0
61	50	Biased	5	4	-1
63	100	Biased	4	4	0
64	100	Biased	4	4	0
65	100	Biased	4	4	0
66	50	Unbiased	4	4	0
67	50	Unbiased	4	4	0
68	50	Unbiased	4	4	0
69	100	Unbiased	4	4	0
70	100	Unbiased	4	4	0
71	100	Unbiased	4	4	0
72	0	Control	4	4	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4	4	4		4	4	4		0	0	0	
50	4	4.1667	5	0.40825	4	4	4	0	-1	-0.16667	0	0.40825
100	4	4	4	0	4	4	4	0	0	0	0	0

Device Test: 122.1 Min Input PW Static HS Turn Off VIN_14V





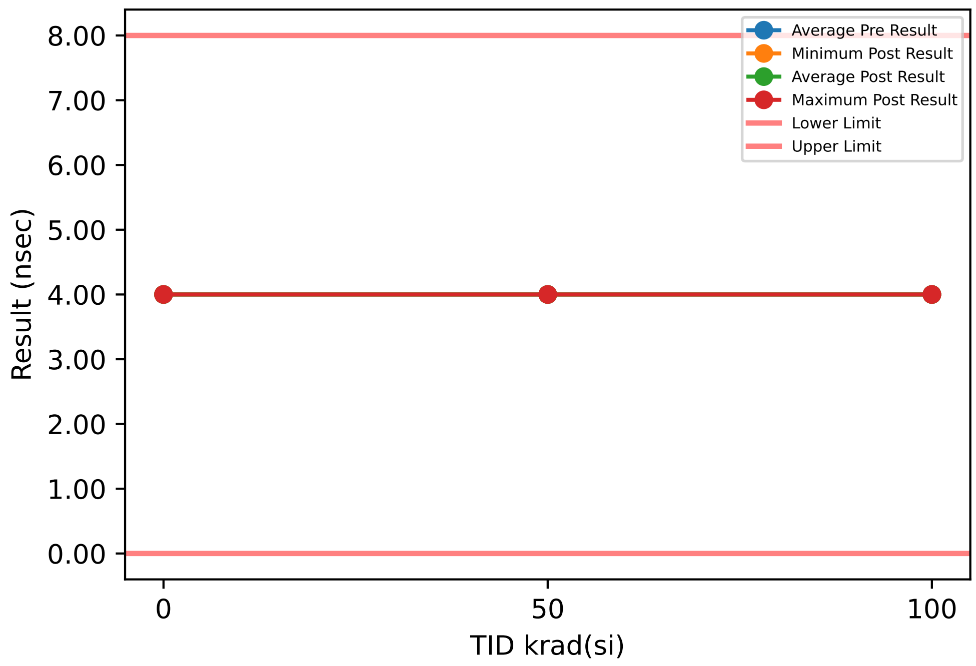
Test Results (Lower Limit = 0.0, Upper Limit = 12.0 (nsec))

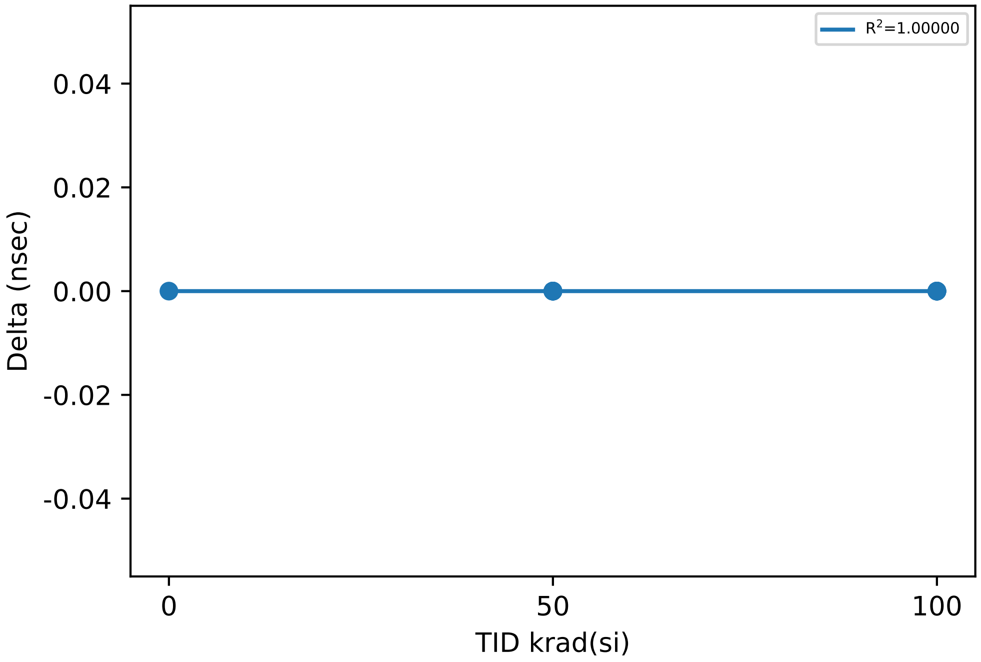
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6	6	0
60	50	Biased	6	6	0
61	50	Biased	6	6	0
63	100	Biased	6	6	0
64	100	Biased	6	6	0
65	100	Biased	5	5	0
66	50	Unbiased	6	6	0
67	50	Unbiased	6	6	0
68	50	Unbiased	6	6	0
69	100	Unbiased	6	6	0
70	100	Unbiased	6	6	0
71	100	Unbiased	6	6	0
72	0	Control	7	7	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7	7	7		7	7	7		0	0	0	
50	6	6	6	0	6	6	6	0	0	0	0	0
100	5	5.8333	6	0.40825	5	5.8333	6	0.40825	0	0	0	0

Device Test: 122.2 Min Input PW Static LS Turn On VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

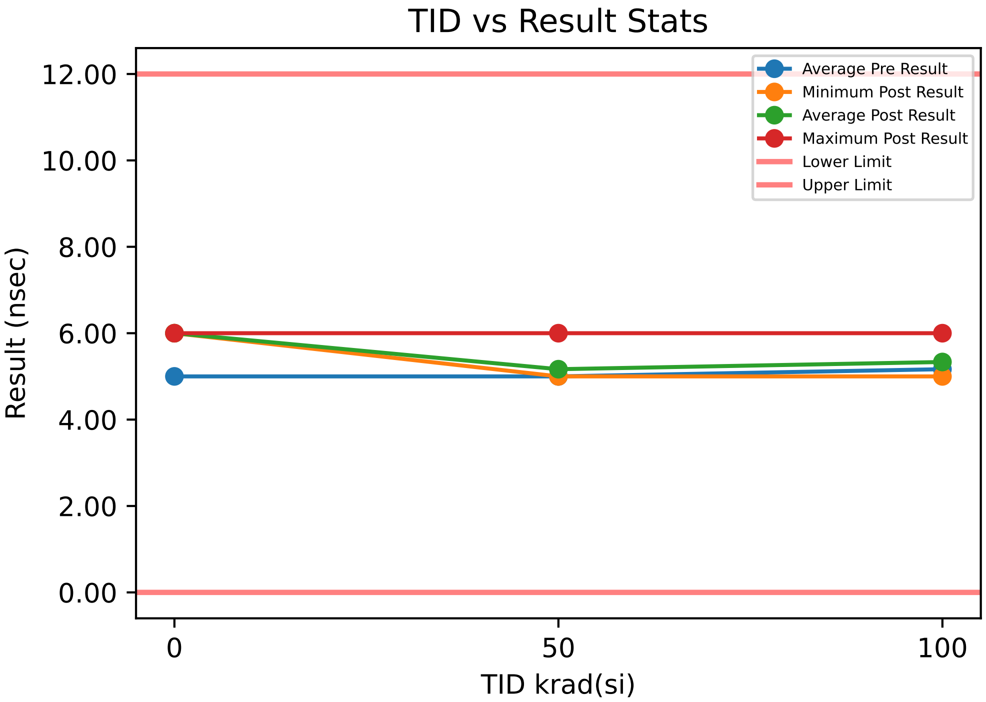
Test Results (Lower Limit = 0.0, Upper Limit = 8.0 (nsec))

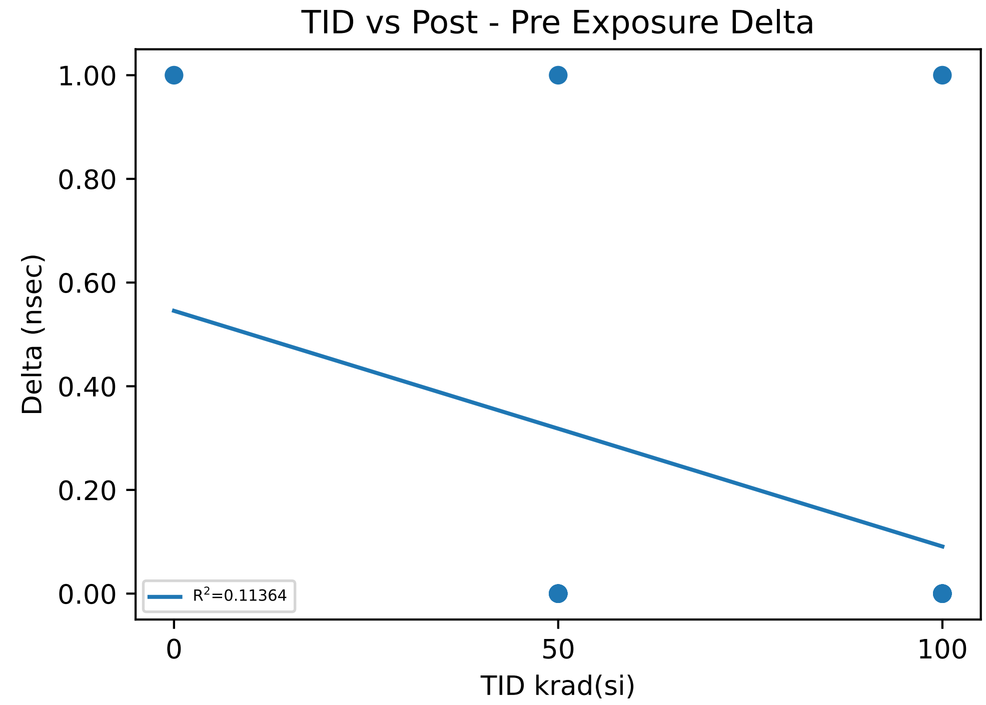
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4	4	0
60	50	Biased	4	4	0
61	50	Biased	4	4	0
63	100	Biased	4	4	0
64	100	Biased	4	4	0
65	100	Biased	4	4	0
66	50	Unbiased	4	4	0
67	50	Unbiased	4	4	0
68	50	Unbiased	4	4	0
69	100	Unbiased	4	4	0
70	100	Unbiased	4	4	0
71	100	Unbiased	4	4	0
72	0	Control	4	4	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4	4	4		4	4	4		0	0	0	
50	4	4	4	0	4	4	4	0	0	0	0	0
100	4	4	4	0	4	4	4	0	0	0	0	0

Device Test: 122.3 Min Input PW Static LS Turn Off VIN_14V





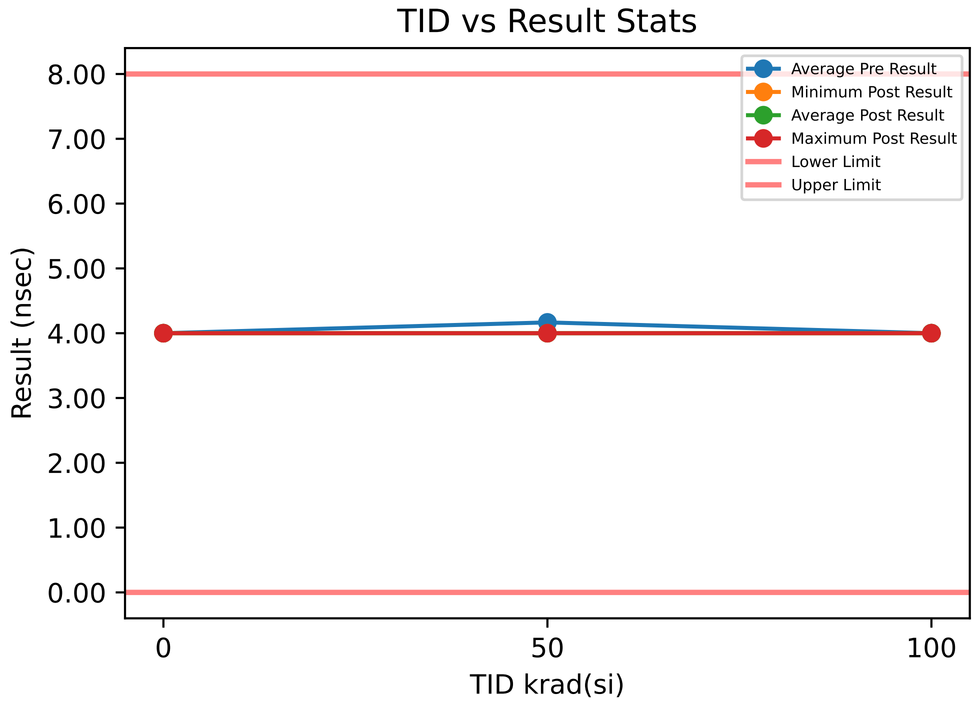
Test Results (Lower Limit = 0.0, Upper Limit = 12.0 (nsec))

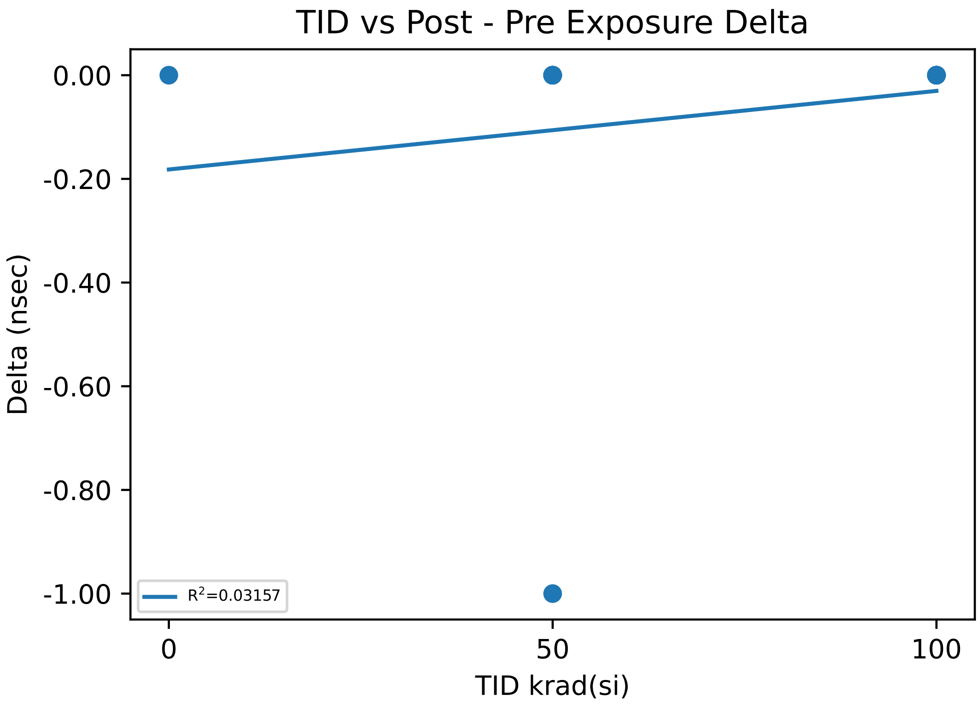
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5	5	0
60	50	Biased	5	6	1
61	50	Biased	5	5	0
63	100	Biased	5	5	0
64	100	Biased	6	6	0
65	100	Biased	5	5	0
66	50	Unbiased	5	5	0
67	50	Unbiased	5	5	0
68	50	Unbiased	5	5	0
69	100	Unbiased	5	5	0
70	100	Unbiased	5	6	1
71	100	Unbiased	5	5	0
72	0	Control	5	6	1

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5		6	6	6		1	1	1	
50	5	5	5	0	5	5.1667	6	0.40825	0	0.16667	1	0.40825
100	5	5.1667	6	0.40825	5	5.3333	6	0.5164	0	0.16667	1	0.40825

Device Test: 122.4 Min Input PW Static HS Turn On SW=100V VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

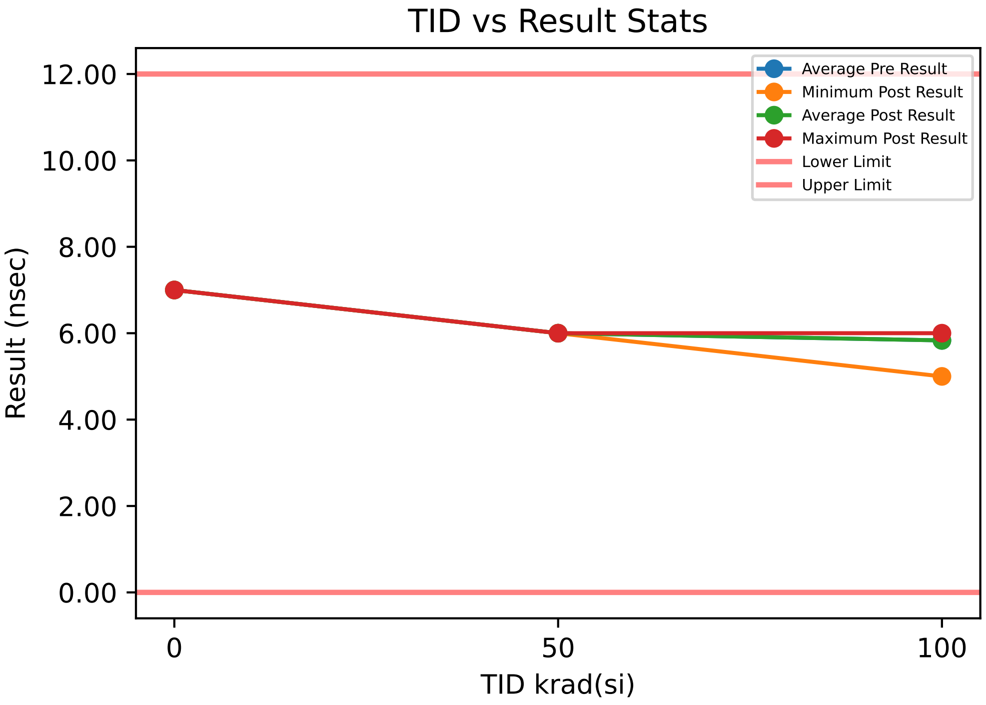
Test Results (Lower Limit = 0.0, Upper Limit = 8.0 (nsec))

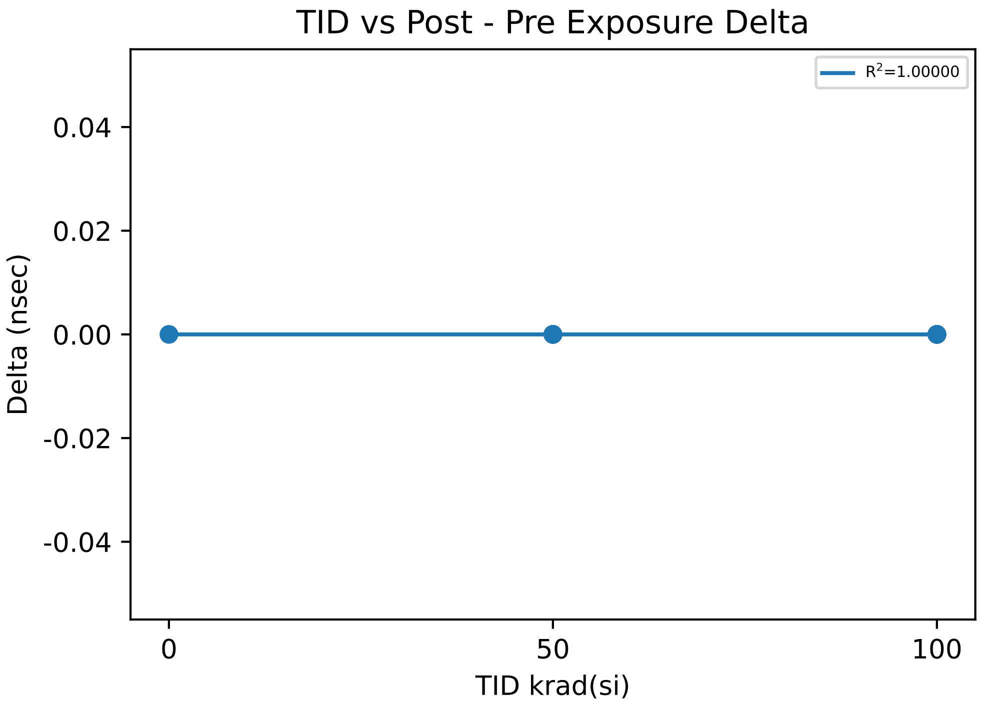
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4	4	0
60	50	Biased	4	4	0
61	50	Biased	5	4	-1
63	100	Biased	4	4	0
64	100	Biased	4	4	0
65	100	Biased	4	4	0
66	50	Unbiased	4	4	0
67	50	Unbiased	4	4	0
68	50	Unbiased	4	4	0
69	100	Unbiased	4	4	0
70	100	Unbiased	4	4	0
71	100	Unbiased	4	4	0
72	0	Control	4	4	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4	4	4		4	4	4		0	0	0	
50	4	4.1667	5	0.40825	4	4	4	0	-1	-0.16667	0	0.40825
100	4	4	4	0	4	4	4	0	0	0	0	0

Device Test: 122.5 Min Input PW Static HS Turn Off SW=100V VIN_14V





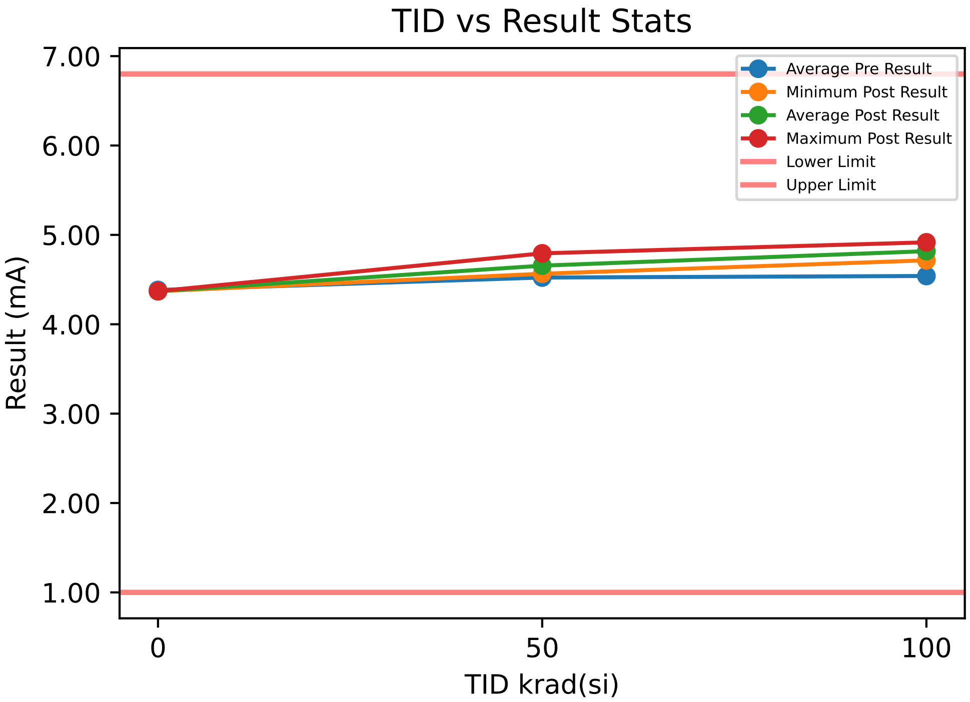
Test Results (Lower Limit = 0.0, Upper Limit = 12.0 (nsec))

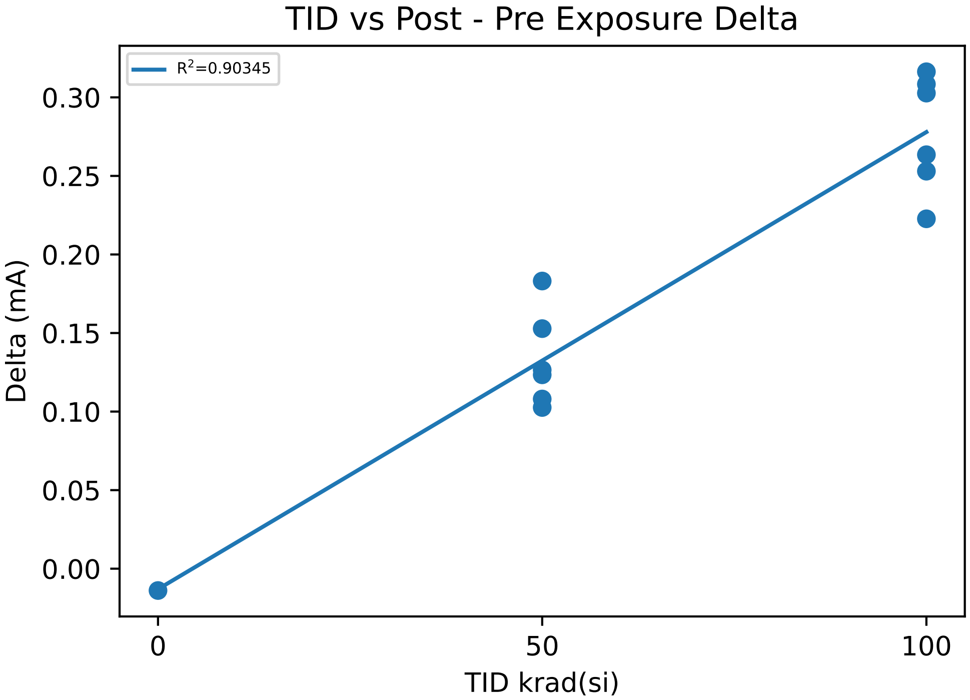
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6	6	0
60	50	Biased	6	6	0
61	50	Biased	6	6	0
63	100	Biased	6	6	0
64	100	Biased	6	6	0
65	100	Biased	5	5	0
66	50	Unbiased	6	6	0
67	50	Unbiased	6	6	0
68	50	Unbiased	6	6	0
69	100	Unbiased	6	6	0
70	100	Unbiased	6	6	0
71	100	Unbiased	6	6	0
72	0	Control	7	7	0

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7	7	7		7	7	7		0	0	0	
50	6	6	6	0	6	6	6	0	0	0	0	0
100	5	5.8333	6	0.40825	5	5.8333	6	0.40825	0	0	0	0

Device Test: 35.0 Iq LS VIN PWM VIN_10V





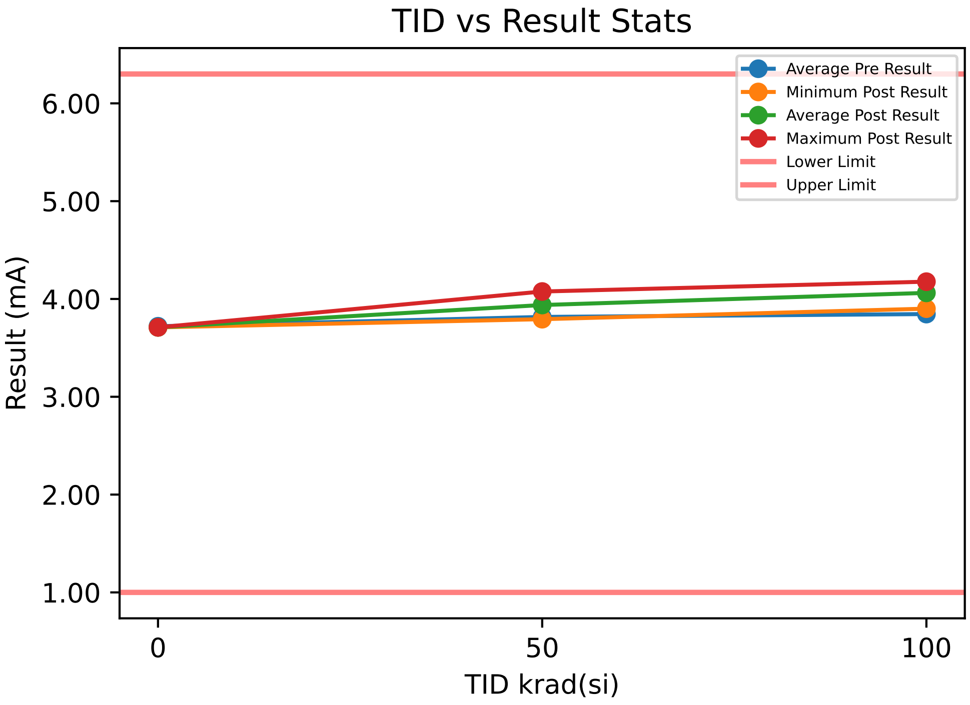
Test Results (Lower Limit = 1.0, Upper Limit = 6.8 (mA))

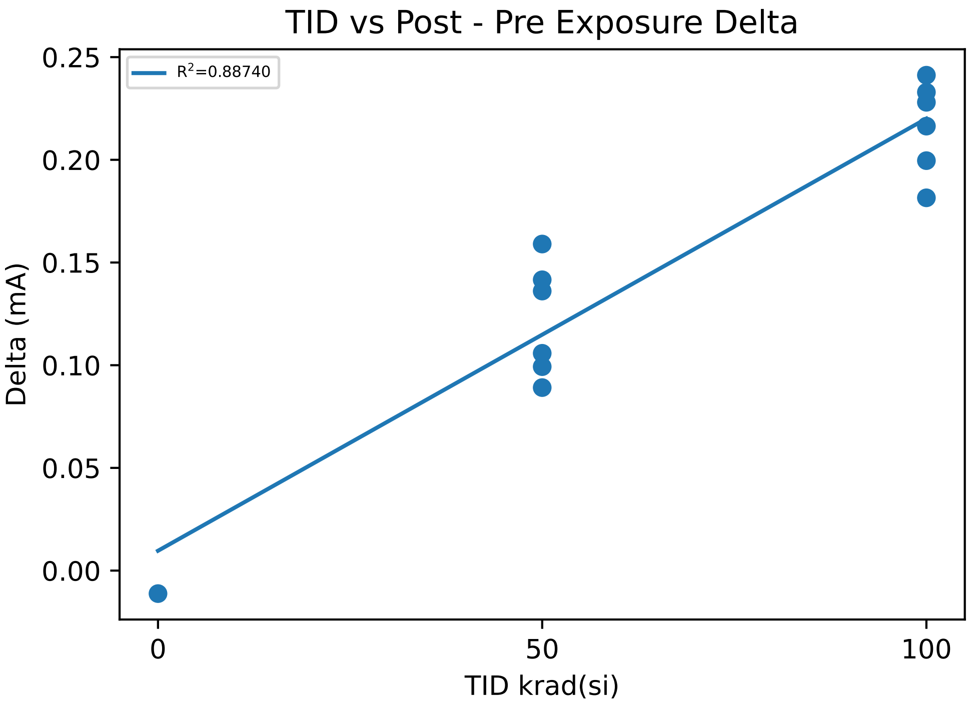
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.4937	4.6202	0.1265
60	50	Biased	4.4947	4.6475	0.1528
61	50	Biased	4.5445	4.6679	0.1234
63	100	Biased	4.5444	4.8607	0.3163
64	100	Biased	4.498	4.7615	0.2635
65	100	Biased	4.4836	4.7366	0.253
66	50	Unbiased	4.5317	4.6397	0.108
67	50	Unbiased	4.4626	4.5652	0.1026
68	50	Unbiased	4.6104	4.7935	0.1831
69	100	Unbiased	4.6076	4.916	0.3084
70	100	Unbiased	4.6138	4.9165	0.3027
71	100	Unbiased	4.4925	4.7152	0.2227
72	0	Control	4.3837	4.3698	-0.0139

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3837	4.3837	4.3837		4.3698	4.3698	4.3698		-0.0139	-0.0139	-0.0139	
50	4.4626	4.5229	4.6104	0.051931	4.5652	4.6557	4.7935	0.076041	0.1026	0.13273	0.1831	0.030283
100	4.4836	4.54	4.6138	0.058714	4.7152	4.8178	4.9165	0.091121	0.2227	0.27777	0.3163	0.037133

Device Test: 35.1 Iq HS BOOT PWM VIN_10V





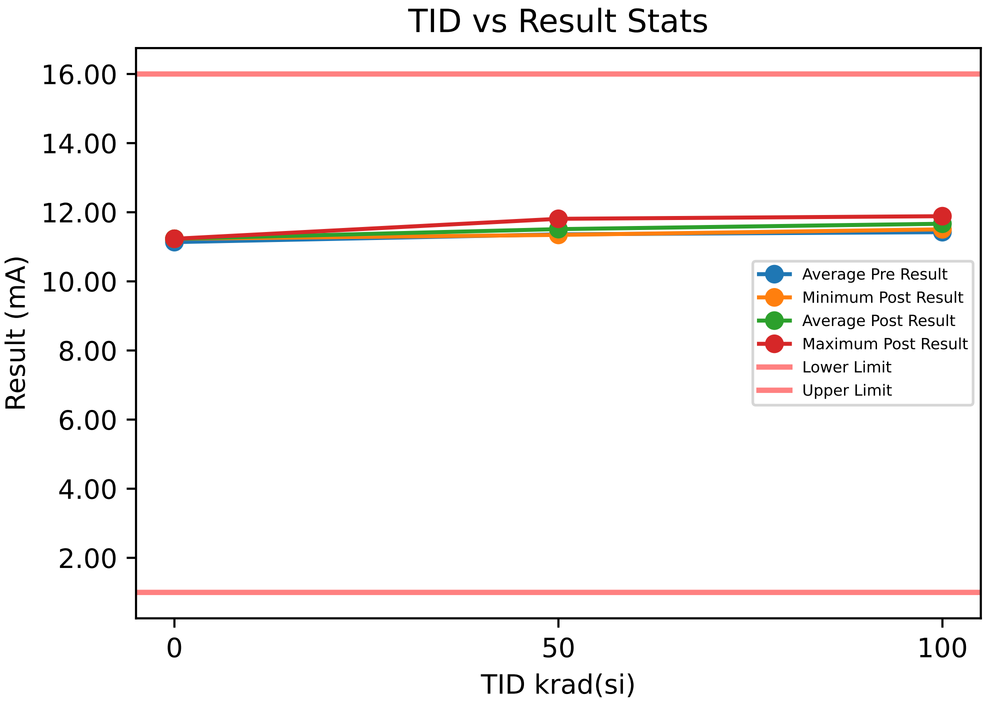
Test Results (Lower Limit = 1.0, Upper Limit = 6.3 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.6939	3.7932	0.0993
60	50	Biased	3.805	3.9466	0.1416
61	50	Biased	3.6818	3.8408	0.159
63	100	Biased	3.8322	4.0651	0.2329
64	100	Biased	3.7195	3.901	0.1815
65	100	Biased	3.9487	4.1767	0.228
66	50	Unbiased	3.9871	4.0762	0.0891
67	50	Unbiased	3.9249	4.061	0.1361
68	50	Unbiased	3.805	3.9108	0.1058
69	100	Unbiased	3.8138	4.0134	0.1996
70	100	Unbiased	3.8605	4.1017	0.2412
71	100	Unbiased	3.8986	4.115	0.2164
72	0	Control	3.7209	3.7097	-0.0112

Test Statistics (mA)

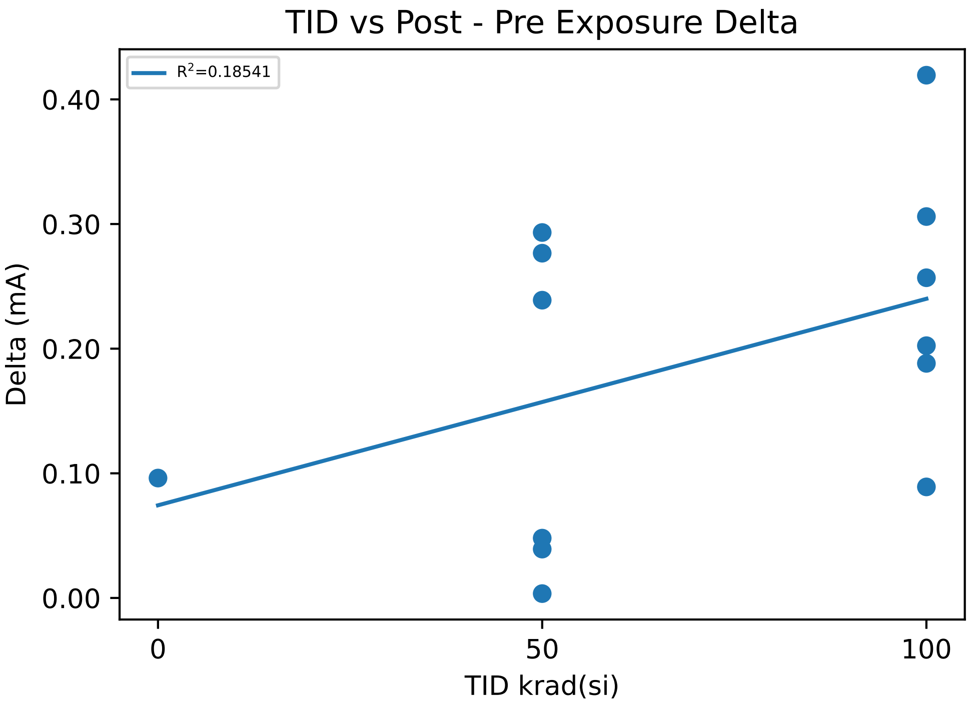
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7209	3.7209	3.7209		3.7097	3.7097	3.7097		-0.0112	-0.0112	-0.0112	
50	3.6818	3.8163	3.9871	0.1219	3.7932	3.9381	4.0762	0.11442	0.0891	0.12182	0.159	0.027611
100	3.7195	3.8455	3.9487	0.078425	3.901	4.0621	4.1767	0.095743	0.1815	0.2166	0.2412	0.022458

Device Test: 35.10 Iop LS VIN PWM 2MHz VIN_10V



Test Results (Lower Limit = 1.0, Upper Limit = 16.0 (mA))

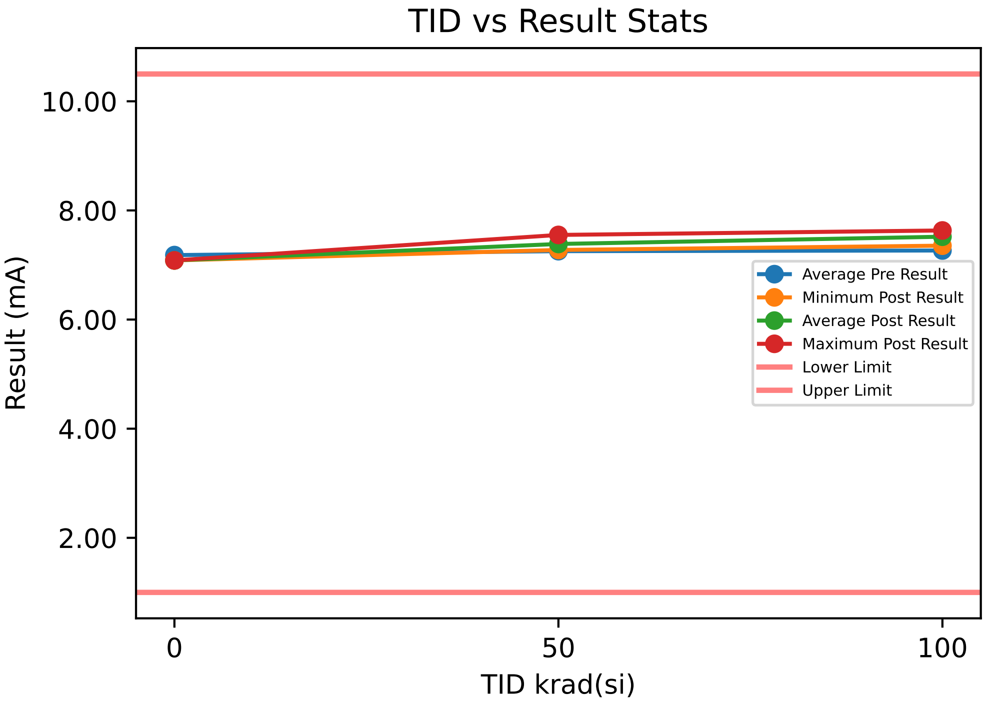
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	11.305	11.352	0.048
60	50	Biased	11.19	11.467	0.2766
61	50	Biased	11.392	11.431	0.0392
63	100	Biased	11.481	11.669	0.1882
64	100	Biased	11.2	11.506	0.306
65	100	Biased	11.385	11.642	0.2569
66	50	Unbiased	11.424	11.663	0.2389
67	50	Unbiased	11.341	11.344	0.0035
68	50	Unbiased	11.517	11.81	0.2932
69	100	Unbiased	11.556	11.759	0.2024
70	100	Unbiased	11.466	11.886	0.4194
71	100	Unbiased	11.453	11.542	0.0891
72	0	Control	11.136	11.232	0.0962

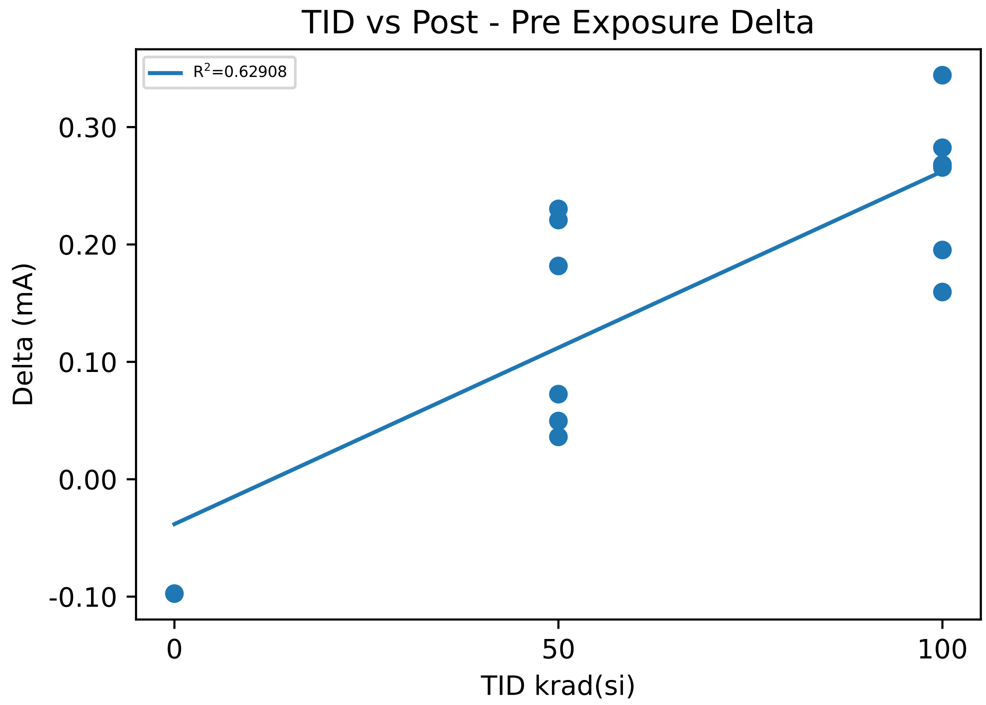


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.136	11.136	11.136		11.232	11.232	11.232		0.0962	0.0962	0.0962	
50	11.19	11.361	11.517	0.11129	11.344	11.511	11.81	0.18643	0.0035	0.1499	0.2932	0.1331
100	11.2	11.424	11.556	0.1225	11.506	11.667	11.886	0.14018	0.0891	0.24367	0.4194	0.11279

Device Test: 35.11 Iop HS BOOT PWM 2MHz VIN_10V





Test Results (Lower Limit = 1.0, Upper Limit = 10.5 (mA))

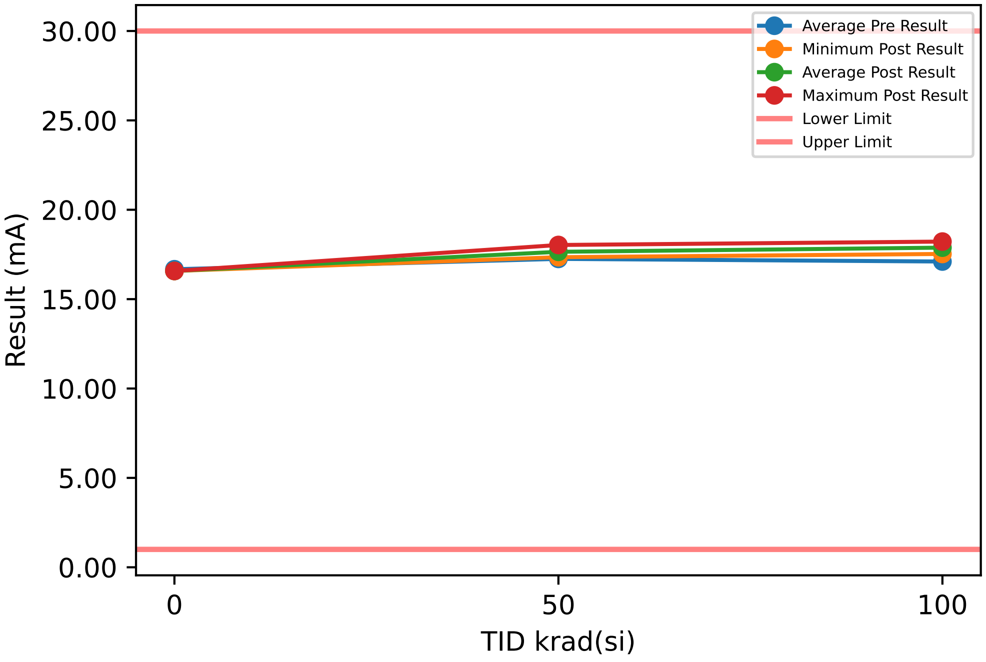
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0937	7.2754	0.1817
60	50	Biased	7.2614	7.3339	0.0725
61	50	Biased	7.0925	7.3228	0.2303
63	100	Biased	7.2475	7.5299	0.2824
64	100	Biased	7.1946	7.3541	0.1595
65	100	Biased	7.3503	7.6159	0.2656
66	50	Unbiased	7.4522	7.4883	0.0361
67	50	Unbiased	7.33	7.5508	0.2208
68	50	Unbiased	7.2901	7.3397	0.0496
69	100	Unbiased	7.207	7.4751	0.2681
70	100	Unbiased	7.305	7.5003	0.1953
71	100	Unbiased	7.2884	7.6326	0.3442
72	0	Control	7.1814	7.084	-0.0974

Test Statistics (mA)

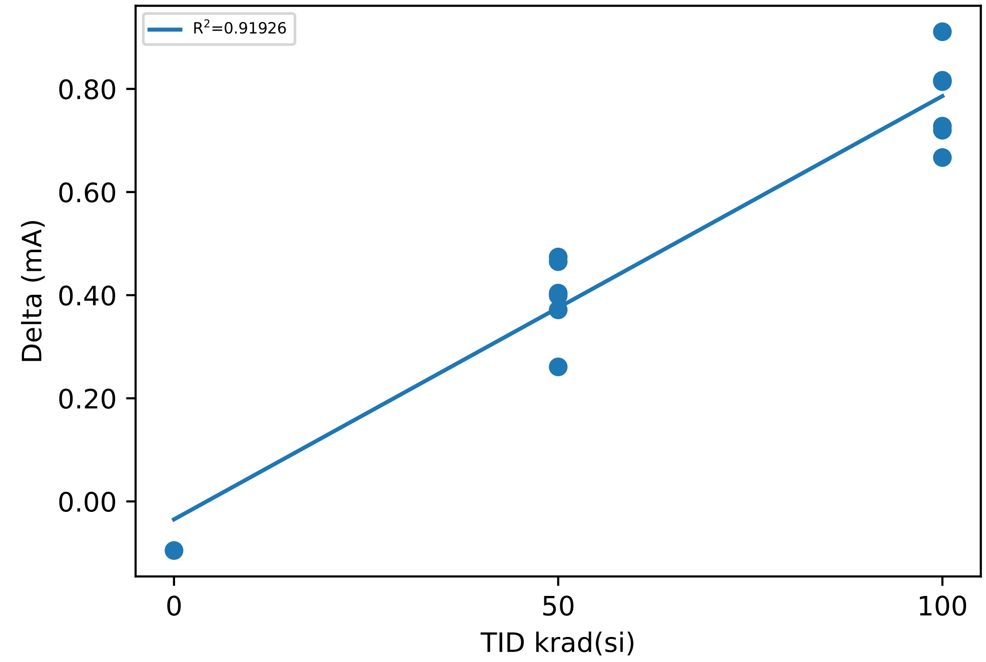
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1814	7.1814	7.1814		7.084	7.084	7.084		-0.0974	-0.0974	-0.0974	
50	7.0925	7.2533	7.4522	0.14014	7.2754	7.3851	7.5508	0.10836	0.0361	0.13183	0.2303	0.088933
100	7.1946	7.2655	7.3503	0.060081	7.3541	7.518	7.6326	0.10186	0.1595	0.25252	0.3442	0.065786

Device Test: 35.12 Iop LS VIN PWM 5MHz VIN_10V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



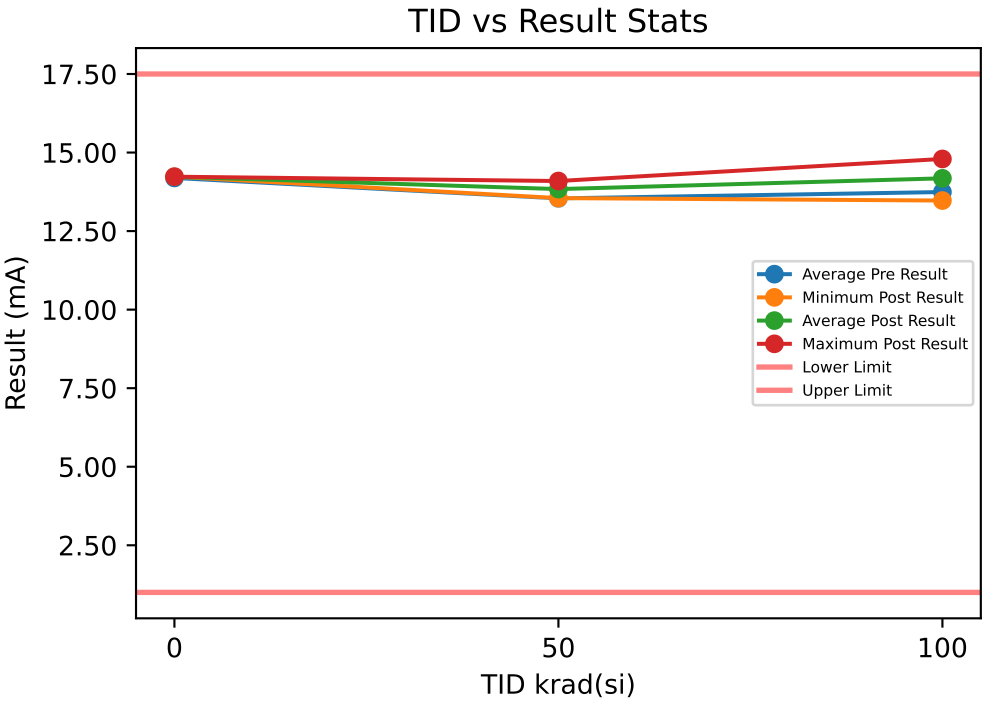
Test Results (Lower Limit = 1.0, Upper Limit = 30.0 (mA))

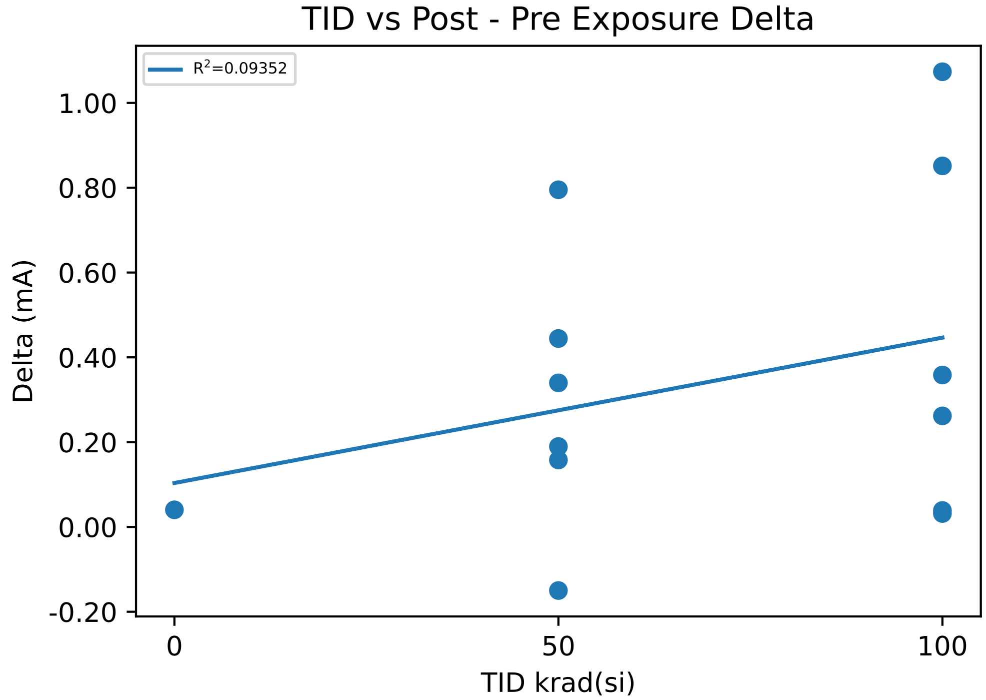
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	17.236	17.64	0.404
60	50	Biased	17.175	17.574	0.3991
61	50	Biased	17.134	17.599	0.465
63	100	Biased	17.273	18.087	0.8141
64	100	Biased	16.894	17.614	0.7199
65	100	Biased	17.071	17.738	0.6669
66	50	Unbiased	17.438	17.699	0.2609
67	50	Unbiased	16.872	17.346	0.474
68	50	Unbiased	17.658	18.029	0.3715
69	100	Unbiased	17.308	18.219	0.9109
70	100	Unbiased	17.37	18.098	0.7278
71	100	Unbiased	16.712	17.529	0.8167
72	0	Control	16.672	16.576	-0.0952

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	16.672	16.672	16.672		16.576	16.576	16.576		-0.0952	-0.0952	-0.0952	
50	16.872	17.252	17.658	0.26977	17.346	17.648	18.029	0.22237	0.2609	0.39575	0.474	0.077163
100	16.712	17.105	17.37	0.26071	17.529	17.881	18.219	0.28975	0.6669	0.77605	0.9109	0.087954

Device Test: 35.13 Iop HS BOOT PWM 5MHz VIN_10V





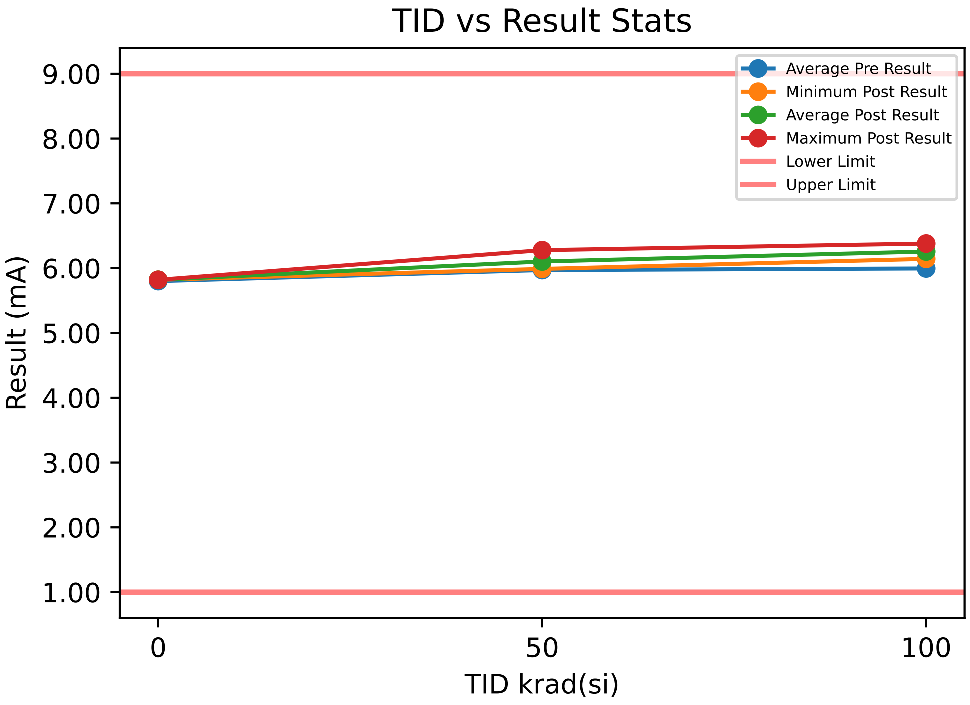
Test Results (Lower Limit = 1.0, Upper Limit = 17.5 (mA))

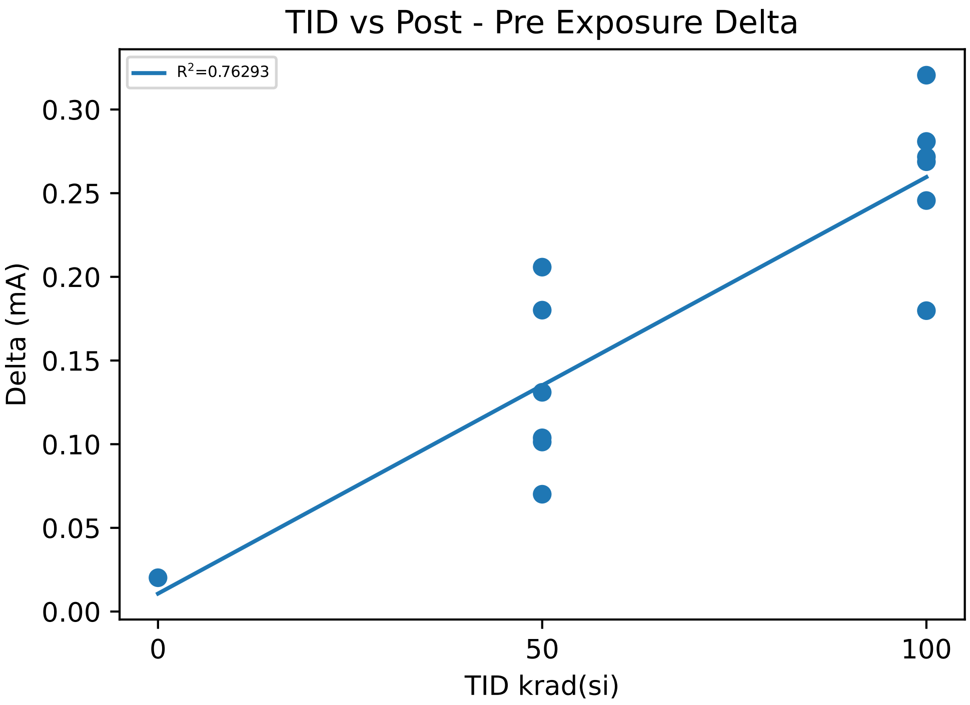
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	13.317	13.657	0.3398
60	50	Biased	13.649	14.094	0.4444
61	50	Biased	13.273	14.068	0.7952
63	100	Biased	13.945	14.796	0.8515
64	100	Biased	13.538	14.611	1.0735
65	100	Biased	14.197	14.235	0.0389
66	50	Unbiased	13.392	13.55	0.1579
67	50	Unbiased	14.2	14.05	-0.1499
68	50	Unbiased	13.413	13.603	0.1896
69	100	Unbiased	13.246	13.604	0.3583
70	100	Unbiased	13.441	13.472	0.0317
71	100	Unbiased	14.093	14.355	0.2619
72	0	Control	14.191	14.232	0.0404

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	14.191	14.191	14.191		14.232	14.232	14.232		0.0404	0.0404	0.0404	
50	13.273	13.541	14.2	0.34846	13.55	13.837	14.094	0.25864	-0.1499	0.29617	0.7952	0.31697
100	13.246	13.743	14.197	0.38716	13.472	14.179	14.796	0.53512	0.0317	0.43597	1.0735	0.43279

Device Test: 35.14 Iop LS VIN IIM Interlock 500kHz VIN_10V





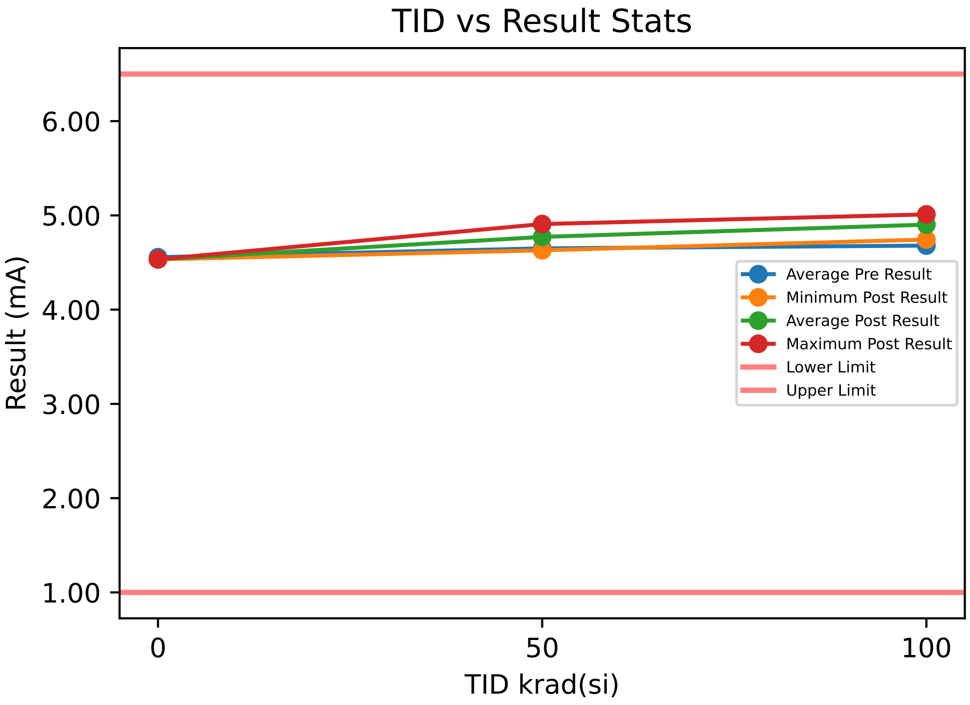
Test Results (Lower Limit = 1.0, Upper Limit = 9.0 (mA))

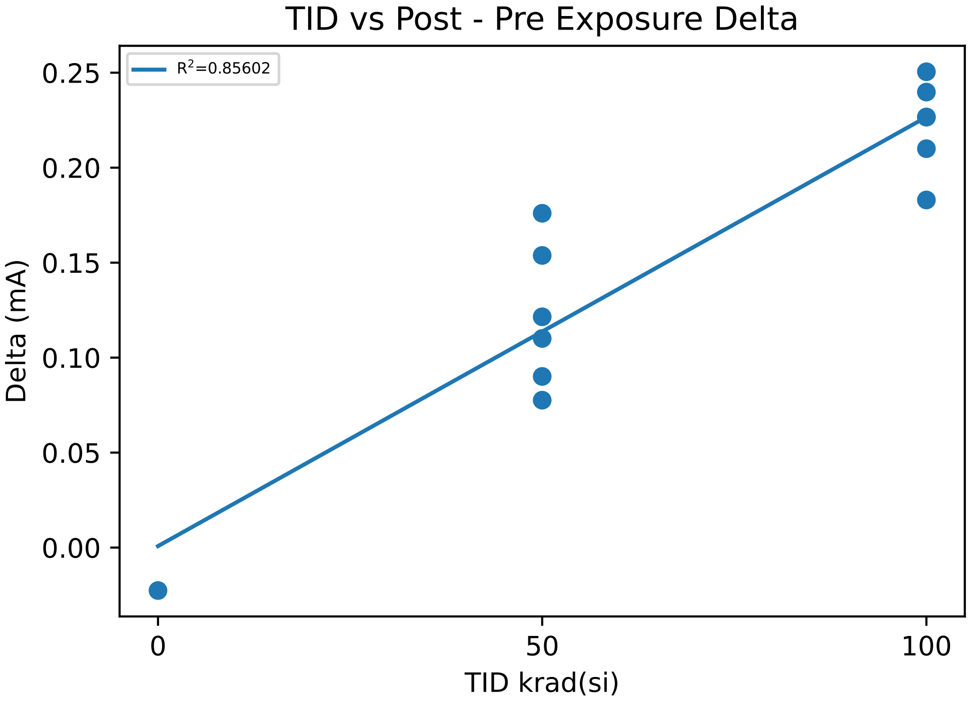
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.9339	6.0377	0.1038
60	50	Biased	5.9029	6.083	0.1801
61	50	Biased	5.9966	6.0979	0.1013
63	100	Biased	6.0163	6.2972	0.2809
64	100	Biased	5.9128	6.1845	0.2717
65	100	Biased	5.9452	6.1908	0.2456
66	50	Unbiased	5.9998	6.1308	0.131
67	50	Unbiased	5.9183	5.9884	0.0701
68	50	Unbiased	6.0721	6.2779	0.2058
69	100	Unbiased	6.0757	6.3445	0.2688
70	100	Unbiased	6.0592	6.3797	0.3205
71	100	Unbiased	5.9637	6.1435	0.1798
72	0	Control	5.8002	5.8204	0.0202

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8002	5.8002	5.8002		5.8204	5.8204	5.8204		0.0202	0.0202	0.0202	
50	5.9029	5.9706	6.0721	0.064026	5.9884	6.1026	6.2779	0.099182	0.0701	0.13202	0.2058	0.051634
100	5.9128	5.9955	6.0757	0.065273	6.1435	6.2567	6.3797	0.096797	0.1798	0.26122	0.3205	0.04678

Device Test: 35.15 Iop HS BOOT IIM Interlock 500kHz VIN_10V





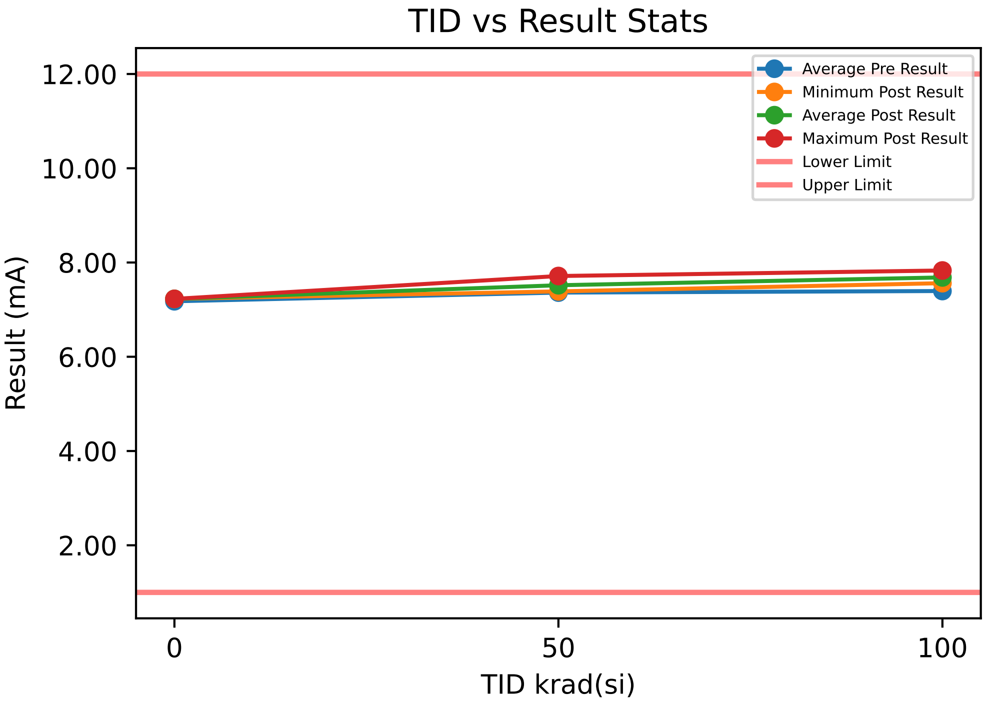
Test Results (Lower Limit = 1.0, Upper Limit = 6.5 (mA))

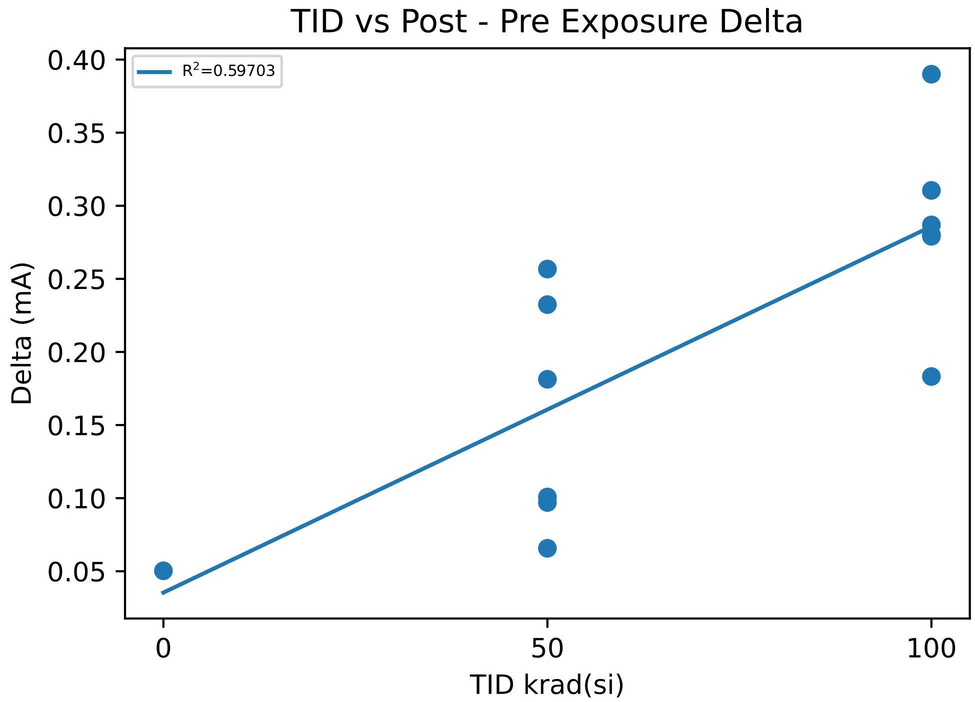
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.5194	4.6295	0.1101
60	50	Biased	4.6439	4.7654	0.1215
61	50	Biased	4.5076	4.6836	0.176
63	100	Biased	4.6607	4.9112	0.2505
64	100	Biased	4.5607	4.7437	0.183
65	100	Biased	4.7836	5.0102	0.2266
66	50	Unbiased	4.825	4.9026	0.0776
67	50	Unbiased	4.7542	4.908	0.1538
68	50	Unbiased	4.65	4.7401	0.0901
69	100	Unbiased	4.6439	4.8539	0.21
70	100	Unbiased	4.6976	4.9243	0.2267
71	100	Unbiased	4.7285	4.9683	0.2398
72	0	Control	4.5561	4.5335	-0.0226

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5561	4.5561	4.5561		4.5335	4.5335	4.5335		-0.0226	-0.0226	-0.0226	
50	4.5076	4.65	4.825	0.12558	4.6295	4.7715	4.908	0.11378	0.0776	0.12152	0.176	0.037568
100	4.5607	4.6792	4.7836	0.076549	4.7437	4.9019	5.0102	0.093869	0.183	0.22277	0.2505	0.023807

Device Test: 35.16 Iop LS VIN IIM Interlock 1MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

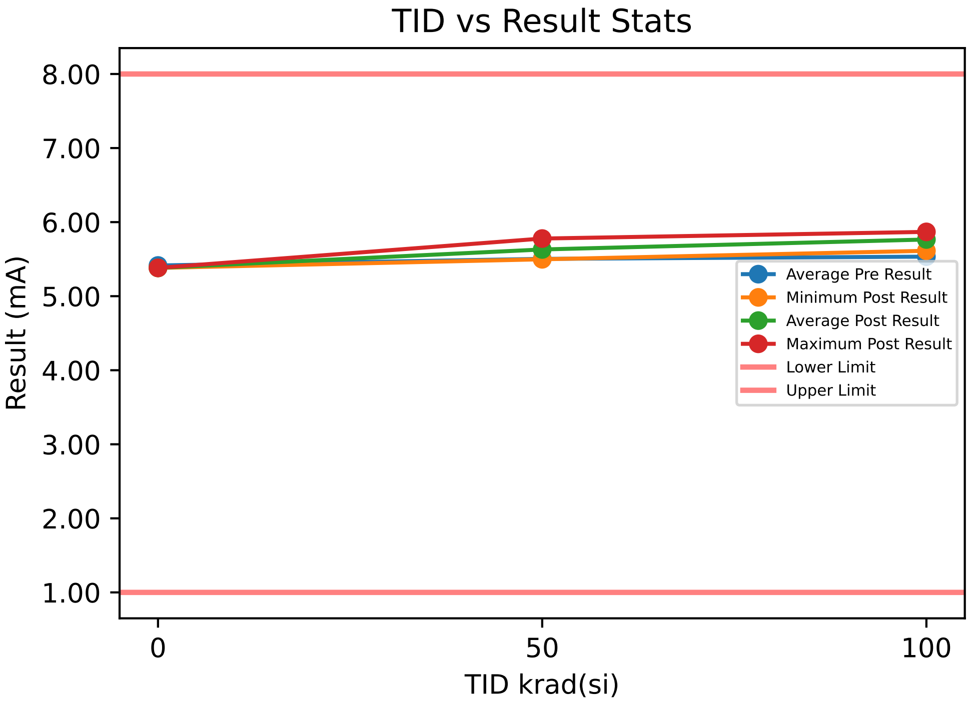
Test Results (Lower Limit = 1.0, Upper Limit = 12.0 (mA))

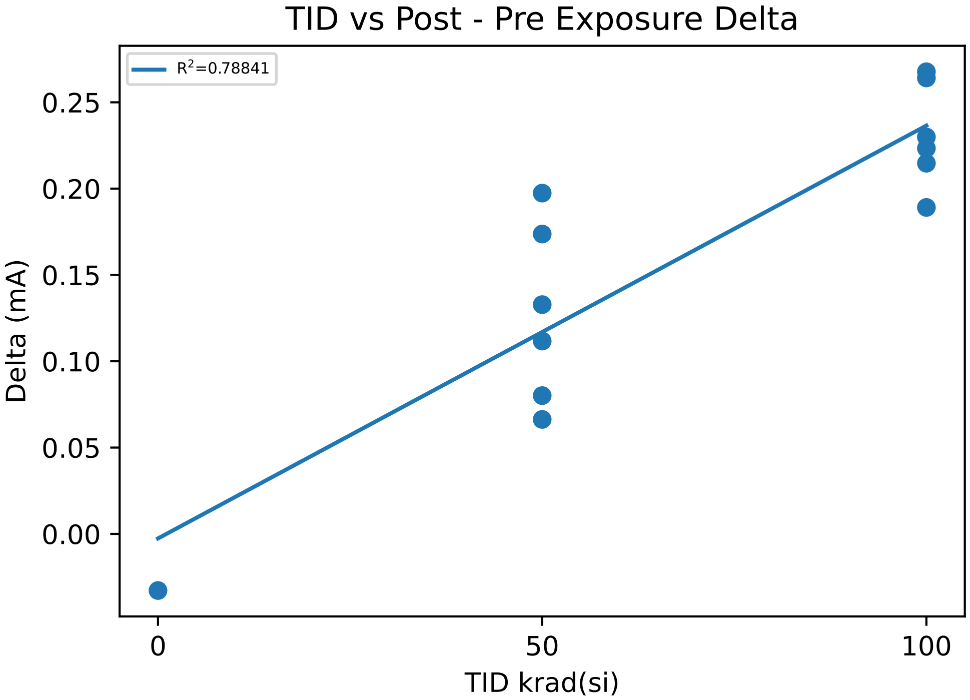
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.3388	7.4396	0.1008
60	50	Biased	7.2756	7.508	0.2324
61	50	Biased	7.398	7.495	0.097
63	100	Biased	7.4187	7.7056	0.2869
64	100	Biased	7.2874	7.5979	0.3105
65	100	Biased	7.3519	7.631	0.2791
66	50	Unbiased	7.3795	7.5608	0.1813
67	50	Unbiased	7.3215	7.3872	0.0657
68	50	Unbiased	7.4566	7.7133	0.2567
69	100	Unbiased	7.4919	7.7722	0.2803
70	100	Unbiased	7.4405	7.8305	0.39
71	100	Unbiased	7.3785	7.5617	0.1832
72	0	Control	7.1775	7.2278	0.0503

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1775	7.1775	7.1775		7.2278	7.2278	7.2278		0.0503	0.0503	0.0503	
50	7.2756	7.3617	7.4566	0.063552	7.3872	7.5173	7.7133	0.11301	0.0657	0.15565	0.2567	0.079119
100	7.2874	7.3948	7.4919	0.071734	7.5617	7.6832	7.8305	0.10477	0.1832	0.28833	0.39	0.066381

Device Test: 35.17 Iop HS BOOT IIM Interlock 1MHz VIN_10V





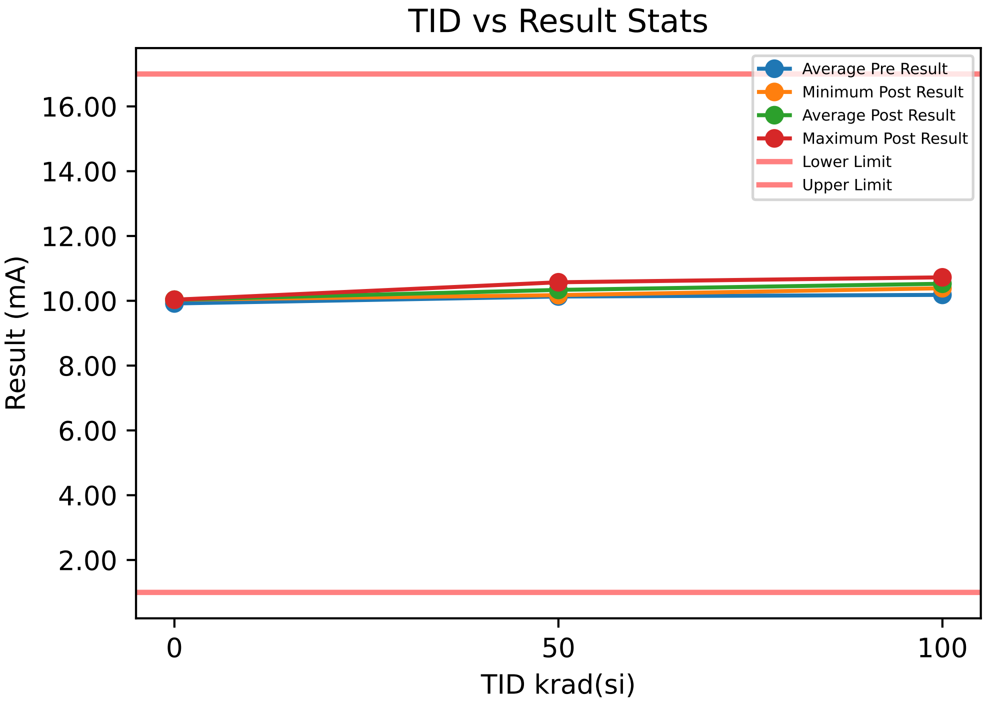
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

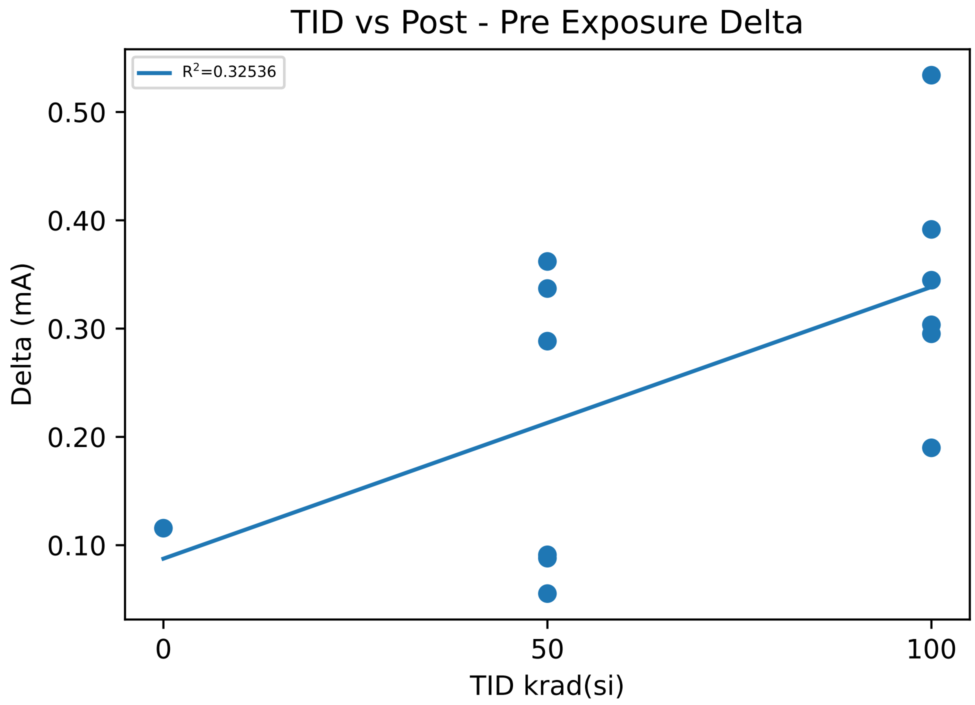
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.3649	5.4977	0.1328
60	50	Biased	5.5003	5.612	0.1117
61	50	Biased	5.3544	5.5518	0.1974
63	100	Biased	5.5126	5.7803	0.2677
64	100	Biased	5.4238	5.6129	0.1891
65	100	Biased	5.6382	5.8681	0.2299
66	50	Unbiased	5.6845	5.7508	0.0663
67	50	Unbiased	5.6044	5.7781	0.1737
68	50	Unbiased	5.5131	5.5932	0.0801
69	100	Unbiased	5.495	5.7184	0.2234
70	100	Unbiased	5.5546	5.7693	0.2147
71	100	Unbiased	5.5774	5.8415	0.2641
72	0	Control	5.4145	5.3817	-0.0328

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4145	5.4145	5.4145		5.3817	5.3817	5.3817		-0.0328	-0.0328	-0.0328	
50	5.3544	5.5036	5.6845	0.12999	5.4977	5.6306	5.7781	0.11119	0.0663	0.127	0.1974	0.051554
100	5.4238	5.5336	5.6382	0.073875	5.6129	5.7651	5.8681	0.091696	0.1891	0.23148	0.2677	0.030071

Device Test: 35.18 Iop LS VIN IIM Interlock 2MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

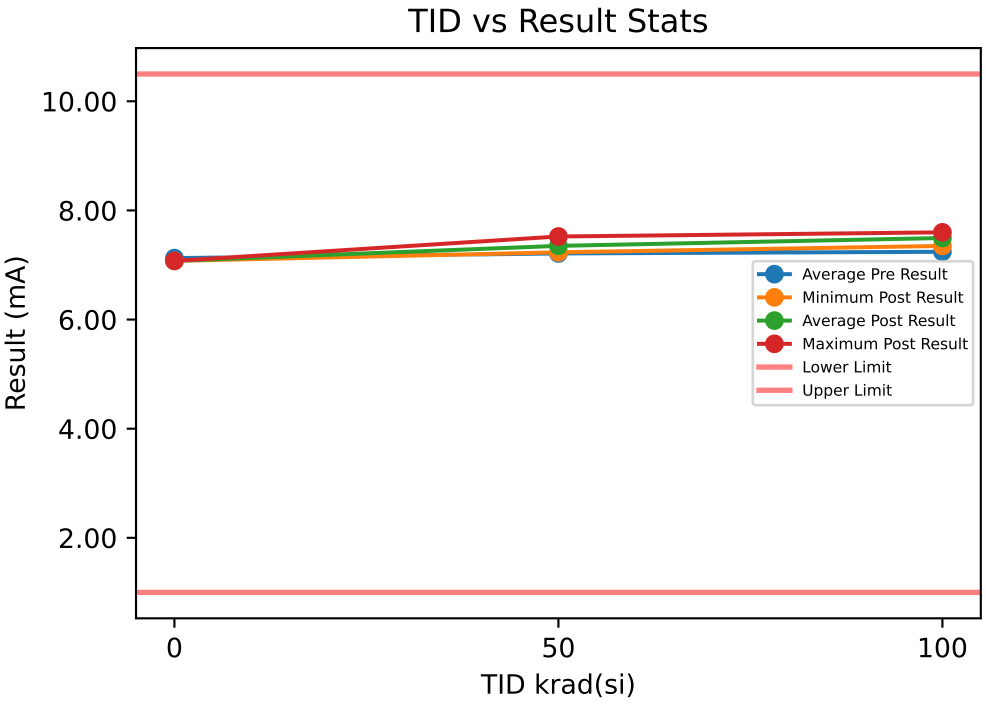
Test Results (Lower Limit = 1.0, Upper Limit = 17.0 (mA))

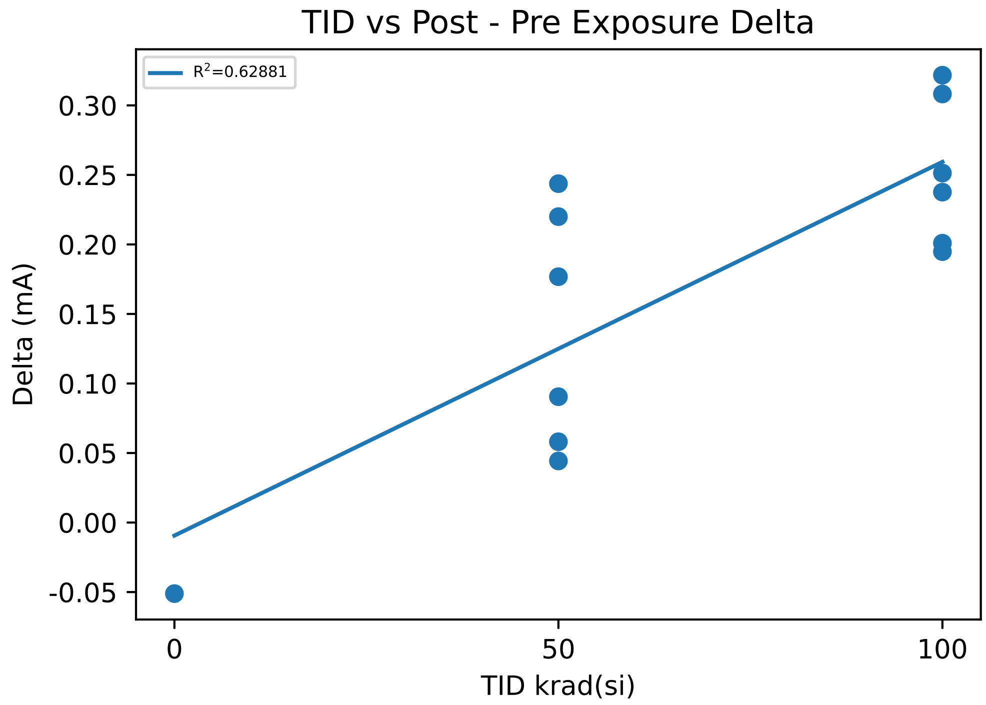
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	10.14	10.231	0.0911
60	50	Biased	10.007	10.344	0.337
61	50	Biased	10.194	10.282	0.088
63	100	Biased	10.217	10.512	0.2952
64	100	Biased	10.024	10.415	0.3916
65	100	Biased	10.157	10.501	0.3447
66	50	Unbiased	10.124	10.412	0.2884
67	50	Unbiased	10.12	10.175	0.0553
68	50	Unbiased	10.21	10.572	0.362
69	100	Unbiased	10.313	10.617	0.3035
70	100	Unbiased	10.19	10.724	0.534
71	100	Unbiased	10.198	10.387	0.1899
72	0	Control	9.9177	10.033	0.1157

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.9177	9.9177	9.9177		10.033	10.033	10.033		0.1157	0.1157	0.1157	
50	10.007	10.132	10.21	0.071745	10.175	10.336	10.572	0.14223	0.0553	0.20363	0.362	0.14006
100	10.024	10.183	10.313	0.094273	10.387	10.526	10.724	0.12627	0.1899	0.34315	0.534	0.115

Device Test: 35.19 Iop HS BOOT IIM Interlock 2MHz VIN_10V





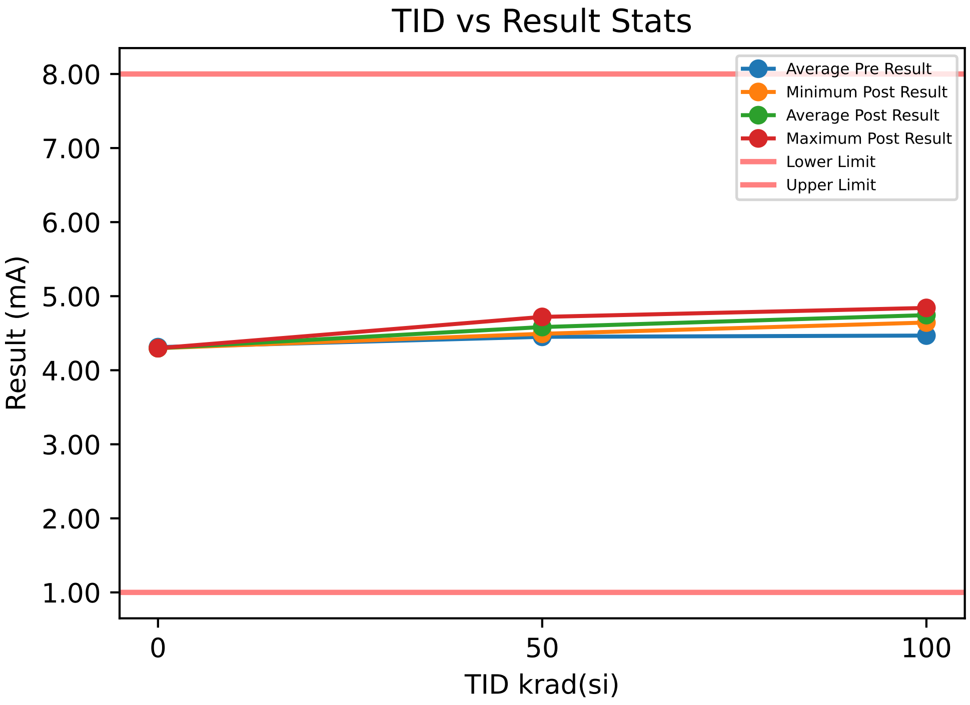
Test Results (Lower Limit = 1.0, Upper Limit = 10.5 (mA))

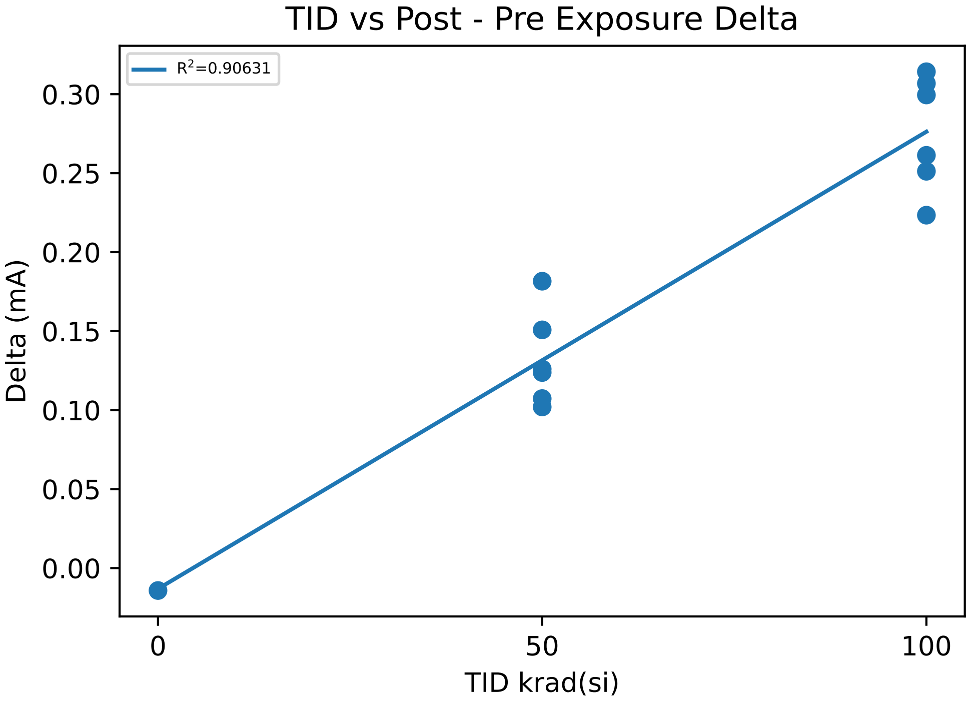
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0553	7.2321	0.1768
60	50	Biased	7.2153	7.3058	0.0905
61	50	Biased	7.0487	7.2924	0.2437
63	100	Biased	7.2139	7.5221	0.3082
64	100	Biased	7.1483	7.3492	0.2009
65	100	Biased	7.3473	7.5849	0.2376
66	50	Unbiased	7.4053	7.4496	0.0443
67	50	Unbiased	7.3022	7.5222	0.22
68	50	Unbiased	7.2424	7.3005	0.0581
69	100	Unbiased	7.195	7.4463	0.2513
70	100	Unbiased	7.2703	7.4651	0.1948
71	100	Unbiased	7.2767	7.5984	0.3217
72	0	Control	7.126	7.0749	-0.0511

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.126	7.126	7.126		7.0749	7.0749	7.0749		-0.0511	-0.0511	-0.0511	
50	7.0487	7.2115	7.4053	0.13975	7.2321	7.3504	7.5222	0.11063	0.0443	0.1389	0.2437	0.08581
100	7.1483	7.2419	7.3473	0.070528	7.3492	7.4943	7.5984	0.093839	0.1948	0.25242	0.3217	0.053116

Device Test: 35.2 Iq LS VIN IIM Interlock VIN_10V





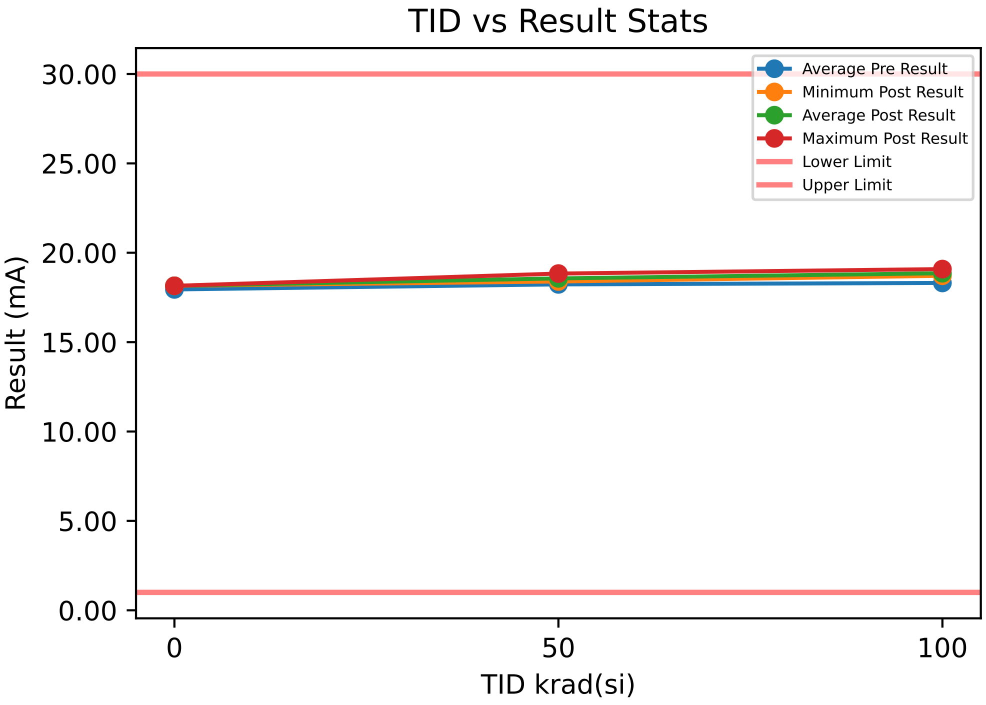
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

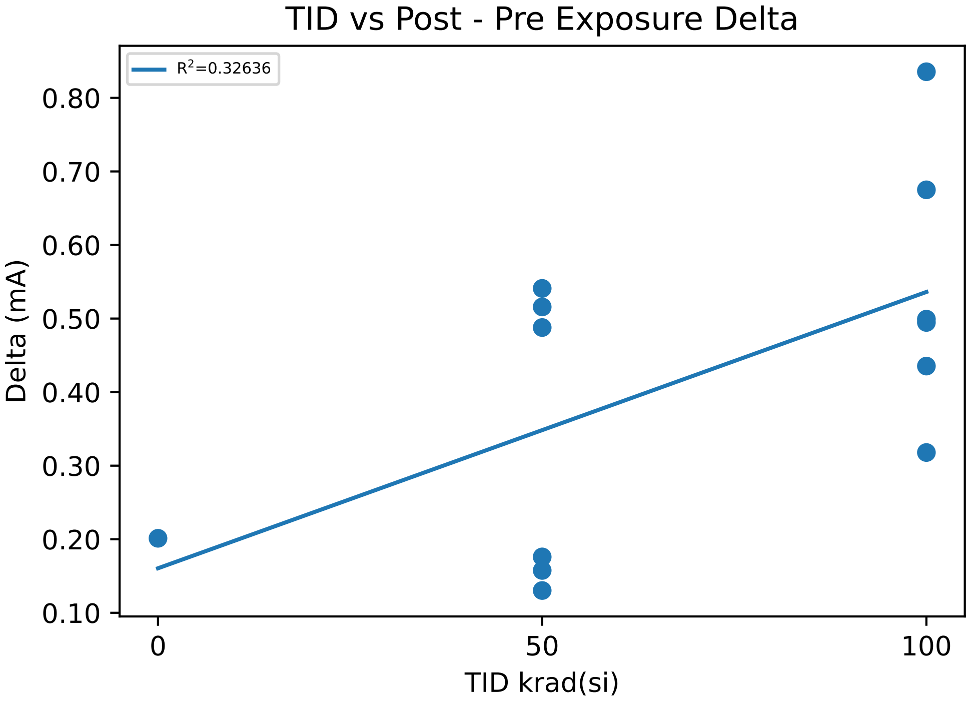
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.4221	4.5481	0.126
60	50	Biased	4.4226	4.5734	0.1508
61	50	Biased	4.4724	4.5962	0.1238
63	100	Biased	4.4726	4.7868	0.3142
64	100	Biased	4.4268	4.6881	0.2613
65	100	Biased	4.4122	4.6634	0.2512
66	50	Unbiased	4.4603	4.5676	0.1073
67	50	Unbiased	4.39	4.492	0.102
68	50	Unbiased	4.5385	4.7201	0.1816
69	100	Unbiased	4.5346	4.8414	0.3068
70	100	Unbiased	4.5413	4.8408	0.2995
71	100	Unbiased	4.4205	4.6439	0.2234
72	0	Control	4.3117	4.2975	-0.0142

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3117	4.3117	4.3117		4.2975	4.2975	4.2975		-0.0142	-0.0142	-0.0142	
50	4.39	4.451	4.5385	0.052084	4.492	4.5829	4.7201	0.075893	0.102	0.13192	0.1816	0.029755
100	4.4122	4.468	4.5413	0.058133	4.6439	4.7441	4.8414	0.089811	0.2234	0.27607	0.3142	0.036216

Device Test: 35.20 Iop LS VIN IIM Interlock 5MHz VIN_10V





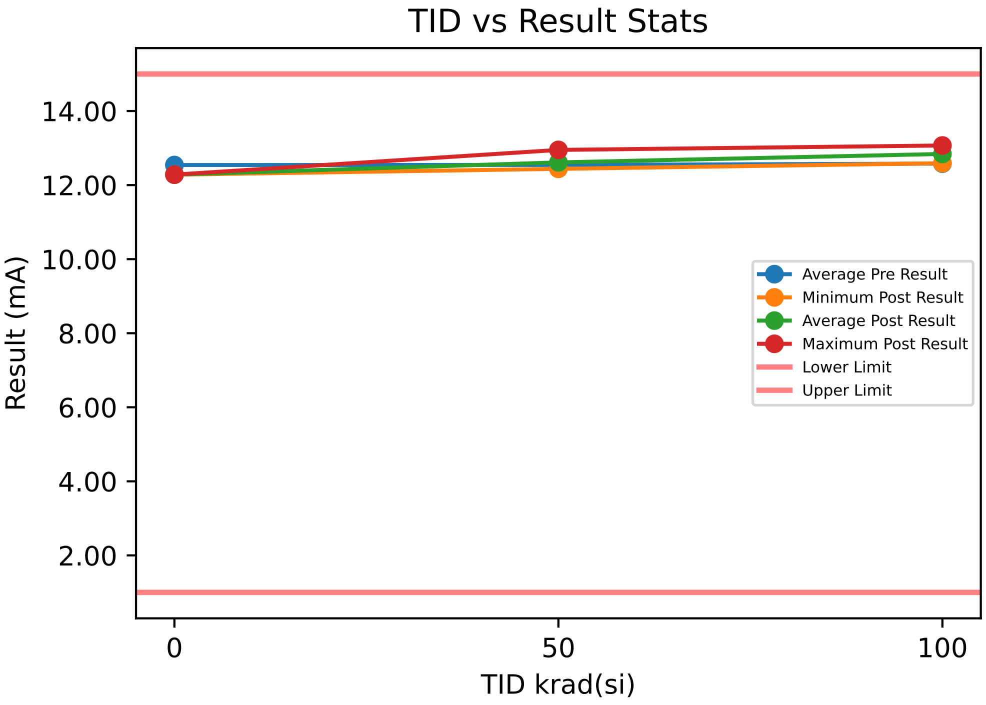
Test Results (Lower Limit = 1.0, Upper Limit = 30.0 (mA))

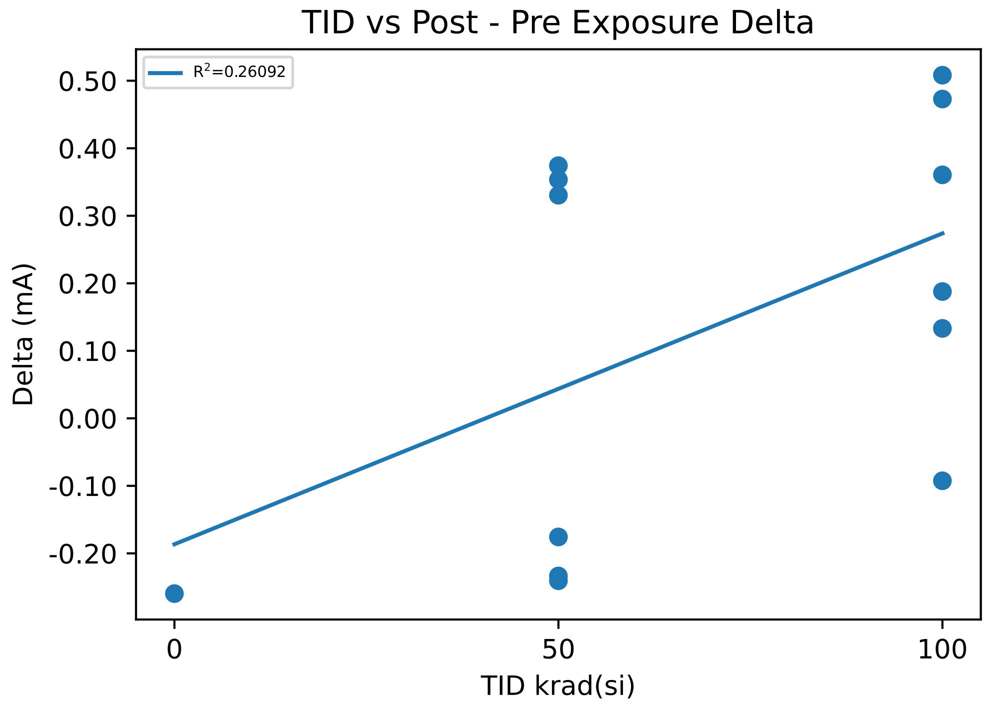
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	18.293	18.469	0.176
60	50	Biased	18.025	18.541	0.5158
61	50	Biased	18.336	18.494	0.1576
63	100	Biased	18.356	18.791	0.4354
64	100	Biased	18.051	18.726	0.675
65	100	Biased	18.311	18.805	0.4947
66	50	Unbiased	18.175	18.663	0.4878
67	50	Unbiased	18.262	18.393	0.1303
68	50	Unbiased	18.295	18.836	0.541
69	100	Unbiased	18.509	19.008	0.4992
70	100	Unbiased	18.251	19.087	0.8355
71	100	Unbiased	18.394	18.712	0.3179
72	0	Control	17.949	18.15	0.2013

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.949	17.949	17.949		18.15	18.15	18.15		0.2013	0.2013	0.2013	
50	18.025	18.231	18.336	0.11438	18.393	18.566	18.836	0.15971	0.1303	0.33475	0.541	0.19856
100	18.051	18.312	18.509	0.15454	18.712	18.855	19.087	0.15556	0.3179	0.54295	0.8355	0.18411

Device Test: 35.21 Iop HS BOOT IIM Interlock 5MHz VIN_10V





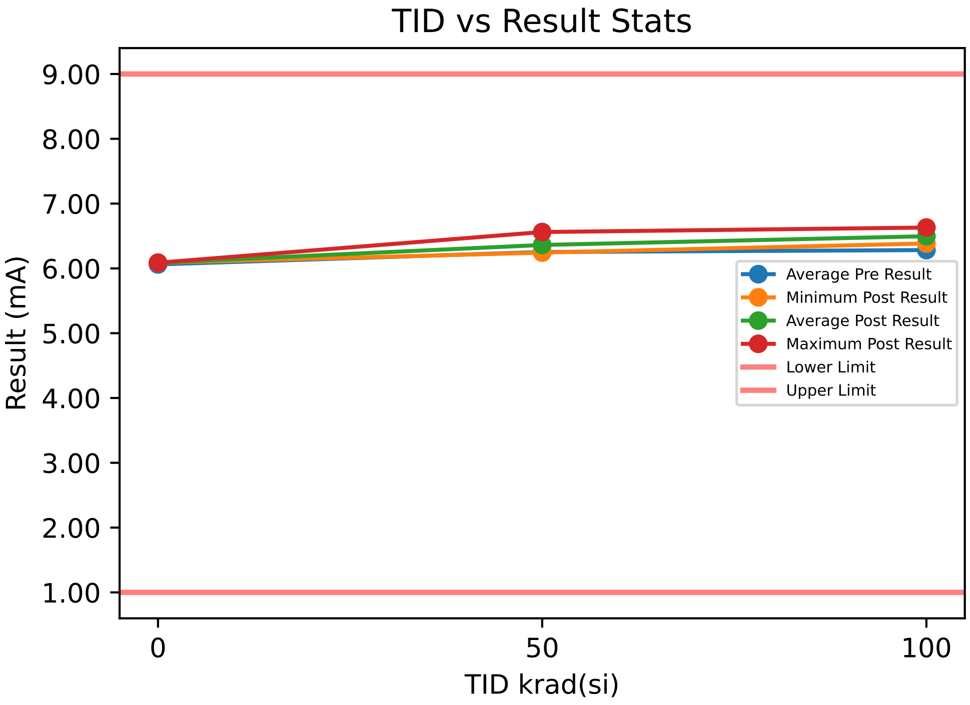
Test Results (Lower Limit = 1.0, Upper Limit = 15.0 (mA))

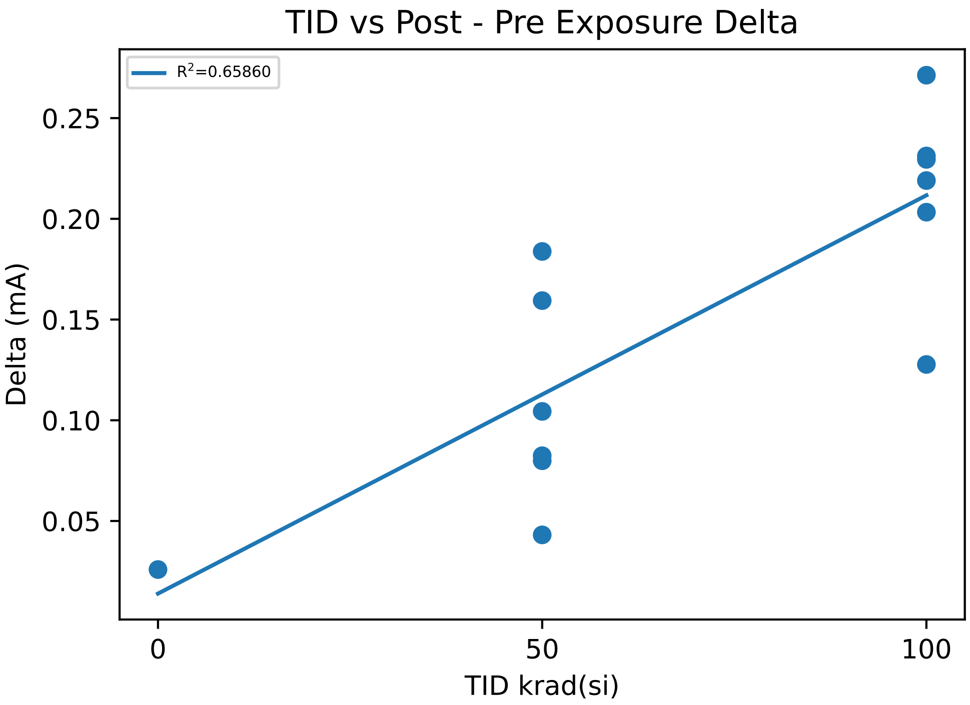
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	12.252	12.605	0.3535
60	50	Biased	12.625	12.45	-0.1757
61	50	Biased	12.284	12.658	0.3742
63	100	Biased	12.477	12.95	0.4729
64	100	Biased	12.588	12.776	0.1878
65	100	Biased	12.717	12.85	0.1332
66	50	Unbiased	12.814	12.573	-0.2406
67	50	Unbiased	12.619	12.95	0.3304
68	50	Unbiased	12.672	12.438	-0.2335
69	100	Unbiased	12.448	12.809	0.3606
70	100	Unbiased	12.684	12.591	-0.0925
71	100	Unbiased	12.561	13.069	0.5082
72	0	Control	12.541	12.282	-0.2596

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.541	12.541	12.541		12.282	12.282	12.282		-0.2596	-0.2596	-0.2596	
50	12.252	12.544	12.814	0.22567	12.438	12.612	12.95	0.18667	-0.2406	0.06805	0.3742	0.31294
100	12.448	12.579	12.717	0.10765	12.591	12.841	13.069	0.16223	-0.0925	0.2617	0.5082	0.22916

Device Test: 35.22 Iop LS VIN IIM Interlock Disable 500kHz VIN_10V





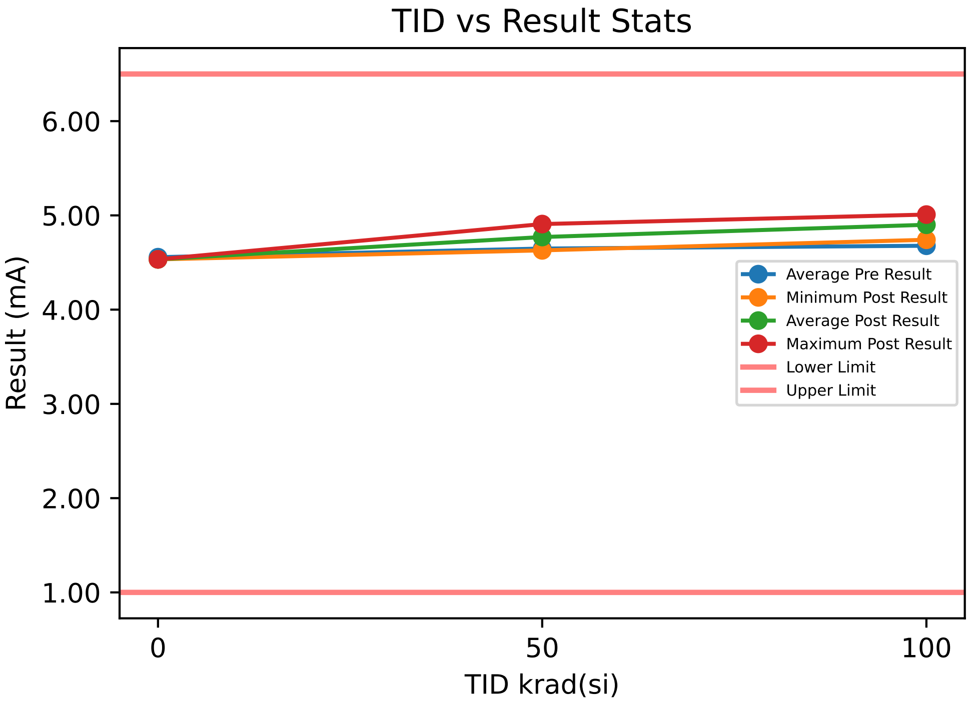
Test Results (Lower Limit = 1.0, Upper Limit = 9.0 (mA))

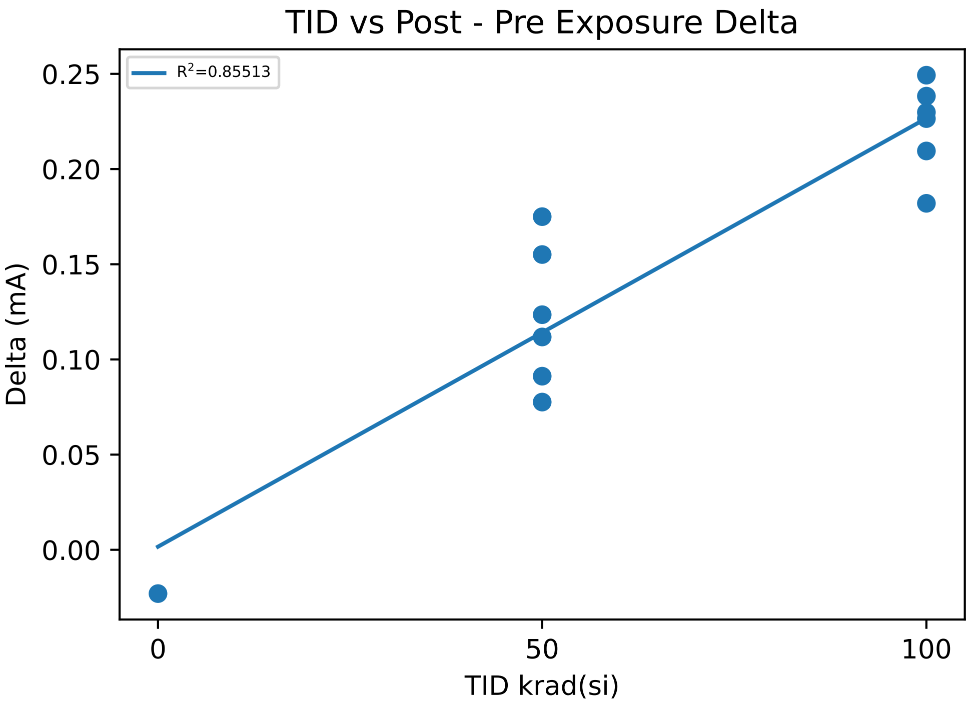
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.1915	6.2739	0.0824
60	50	Biased	6.1585	6.3179	0.1594
61	50	Biased	6.2666	6.3465	0.0799
63	100	Biased	6.3161	6.5456	0.2295
64	100	Biased	6.1709	6.4021	0.2312
65	100	Biased	6.2292	6.4325	0.2033
66	50	Unbiased	6.322	6.4264	0.1044
67	50	Unbiased	6.2003	6.2434	0.0431
68	50	Unbiased	6.3776	6.5614	0.1838
69	100	Unbiased	6.3634	6.5824	0.219
70	100	Unbiased	6.3592	6.6305	0.2713
71	100	Unbiased	6.2573	6.385	0.1277
72	0	Control	6.0614	6.0873	0.0259

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.0614	6.0614	6.0614		6.0873	6.0873	6.0873		0.0259	0.0259	0.0259	
50	6.1585	6.2527	6.3776	0.084806	6.2434	6.3616	6.5614	0.11655	0.0431	0.10883	0.1838	0.053016
100	6.1709	6.2827	6.3634	0.076794	6.385	6.4963	6.6305	0.10314	0.1277	0.21367	0.2713	0.047762

Device Test: 35.23 Iop HS BOOT IIM Interlock Disable 500kHz VIN_10V





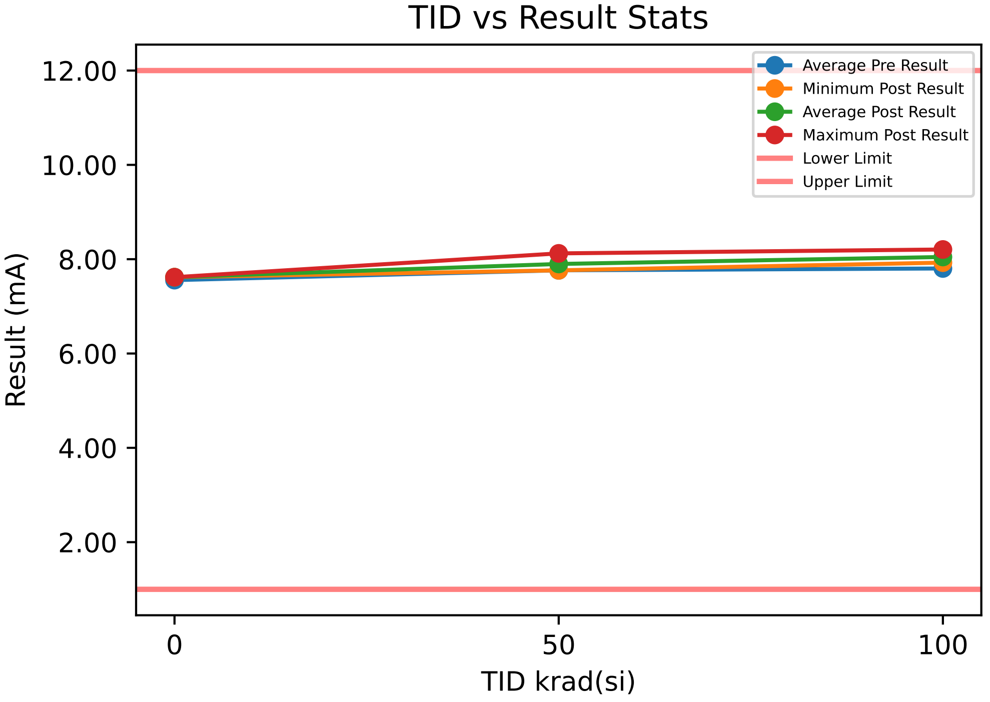
Test Results (Lower Limit = 1.0, Upper Limit = 6.5 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.517	4.6288	0.1118
60	50	Biased	4.6401	4.7636	0.1235
61	50	Biased	4.5059	4.6809	0.175
63	100	Biased	4.6597	4.909	0.2493
64	100	Biased	4.5591	4.7411	0.182
65	100	Biased	4.782	5.0085	0.2265
66	50	Unbiased	4.8237	4.9013	0.0776
67	50	Unbiased	4.7528	4.9079	0.1551
68	50	Unbiased	4.6484	4.7396	0.0912
69	100	Unbiased	4.6434	4.8529	0.2095
70	100	Unbiased	4.6956	4.9254	0.2298
71	100	Unbiased	4.7269	4.9652	0.2383
72	0	Control	4.5564	4.5334	-0.023

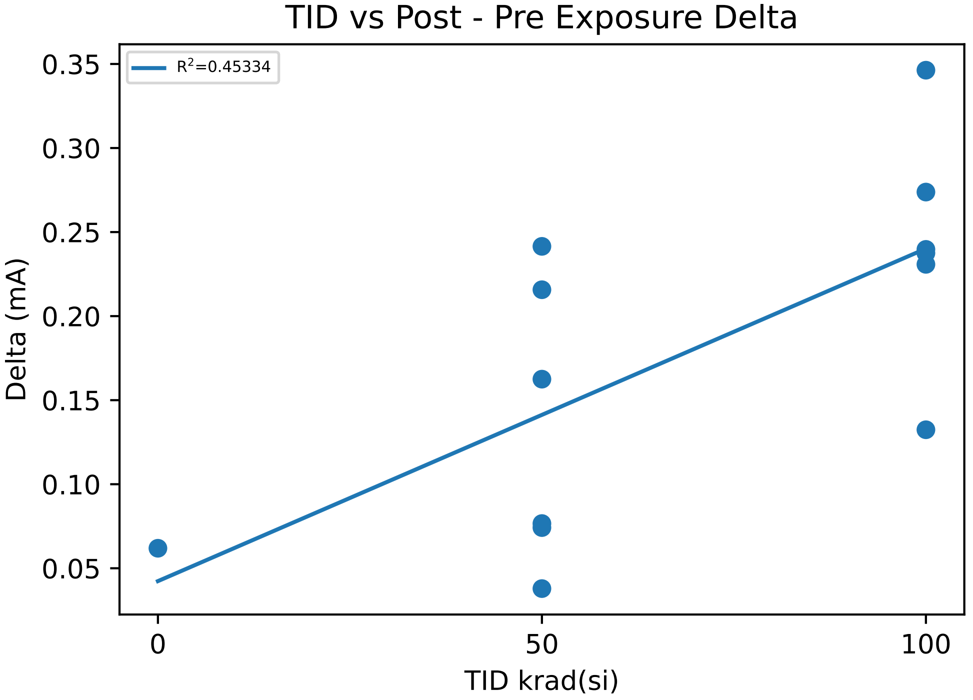
Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5564	4.5564	4.5564		4.5334	4.5334	4.5334		-0.023	-0.023	-0.023	
50	4.5059	4.648	4.8237	0.12591	4.6288	4.7703	4.9079	0.1141	0.0776	0.12237	0.175	0.037229
100	4.5591	4.6778	4.782	0.076402	4.7411	4.9004	5.0085	0.094039	0.182	0.22257	0.2493	0.02386

Device Test: 35.24 Iop LS VIN IIM Interlock Disable 1MHz VIN_10V



TID vs Result Stats



TID vs Post - Pre Exposure Delta

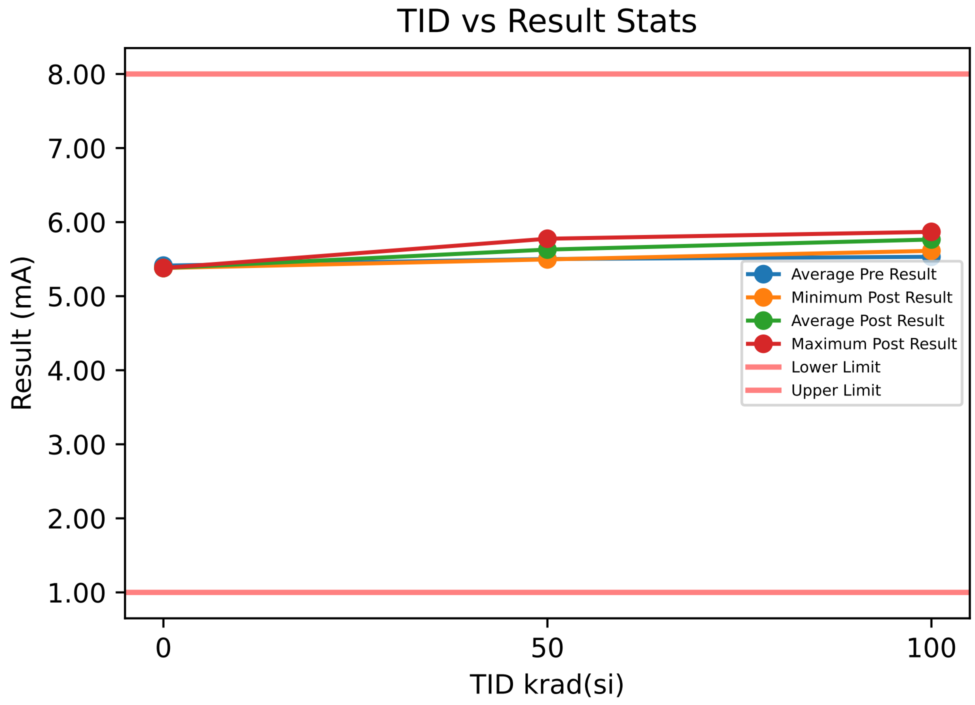
Test Results (Lower Limit = 1.0, Upper Limit = 12.0 (mA))

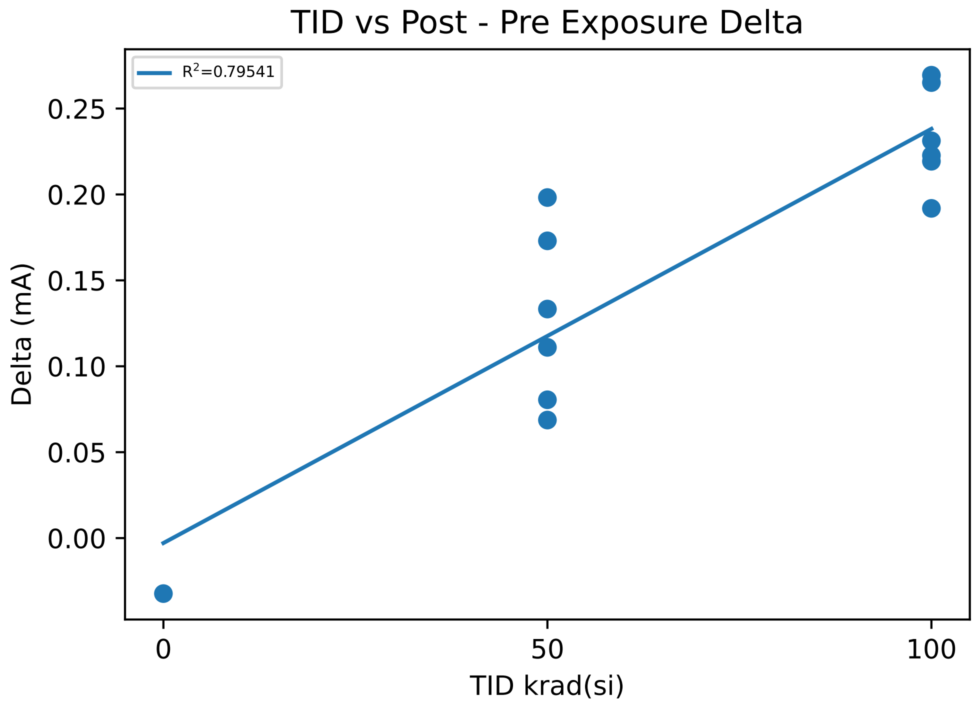
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.7181	7.7947	0.0766
60	50	Biased	7.6491	7.8648	0.2157
61	50	Biased	7.79	7.8642	0.0742
63	100	Biased	7.84	8.0775	0.2375
64	100	Biased	7.6644	7.9382	0.2738
65	100	Biased	7.7588	7.9985	0.2397
66	50	Unbiased	7.819	7.9815	0.1625
67	50	Unbiased	7.7258	7.7637	0.0379
68	50	Unbiased	7.8817	8.1232	0.2415
69	100	Unbiased	7.9022	8.133	0.2308
70	100	Unbiased	7.8594	8.2057	0.3463
71	100	Unbiased	7.7947	7.9271	0.1324
72	0	Control	7.5562	7.6181	0.0619

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.5562	7.5562	7.5562		7.6181	7.6181	7.6181		0.0619	0.0619	0.0619	
50	7.6491	7.764	7.8817	0.082852	7.7637	7.8987	8.1232	0.13314	0.0379	0.13473	0.2415	0.083841
100	7.6644	7.8032	7.9022	0.084407	7.9271	8.0467	8.2057	0.11142	0.1324	0.24342	0.3463	0.069341

Device Test: 35.25 Iop HS BOOT IIM Interlock Disable 1MHz VIN_10V





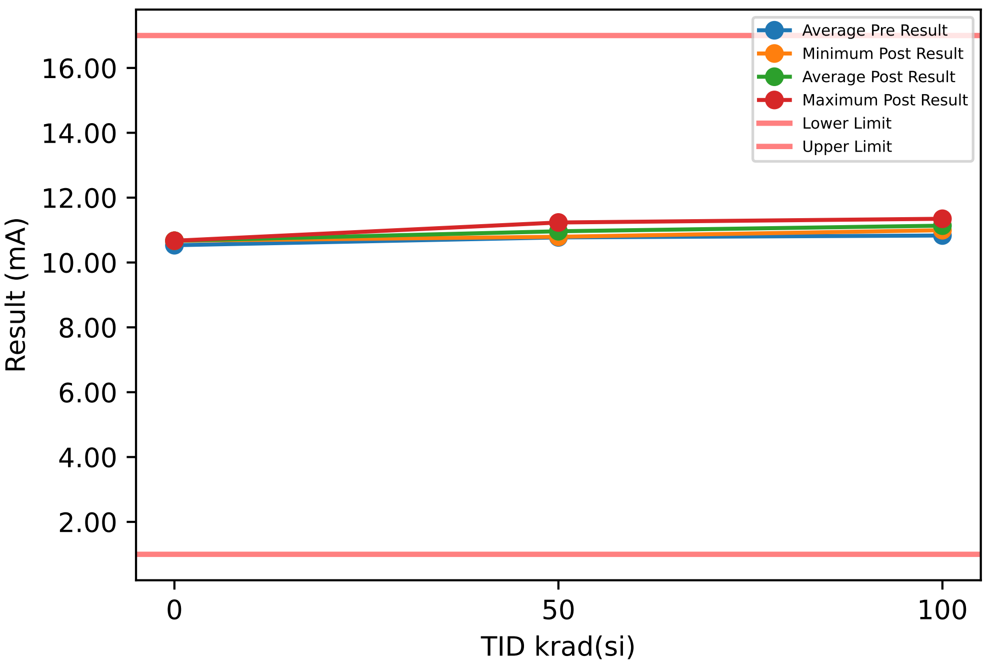
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

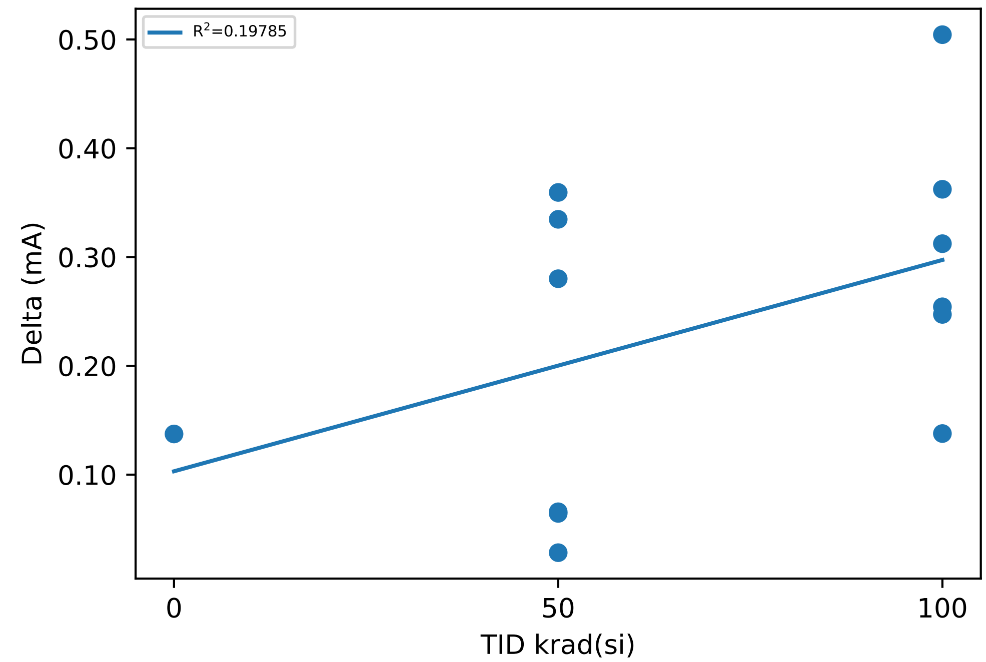
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.3627	5.496	0.1333
60	50	Biased	5.4979	5.6089	0.111
61	50	Biased	5.3525	5.5507	0.1982
63	100	Biased	5.5105	5.7799	0.2694
64	100	Biased	5.4203	5.6122	0.1919
65	100	Biased	5.6371	5.8683	0.2312
66	50	Unbiased	5.6818	5.7505	0.0687
67	50	Unbiased	5.6026	5.7756	0.173
68	50	Unbiased	5.512	5.5925	0.0805
69	100	Unbiased	5.4926	5.7153	0.2227
70	100	Unbiased	5.5529	5.7722	0.2193
71	100	Unbiased	5.5768	5.8419	0.2651
72	0	Control	5.4125	5.3802	-0.0323

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4125	5.4125	5.4125		5.3802	5.3802	5.3802		-0.0323	-0.0323	-0.0323	
50	5.3525	5.5016	5.6818	0.12986	5.496	5.629	5.7756	0.11118	0.0687	0.12745	0.1982	0.051071
100	5.4203	5.5317	5.6371	0.074808	5.6122	5.765	5.8683	0.092386	0.1919	0.23327	0.2694	0.029466

Device Test: 35.26 Iop LS VIN IIM Interlock Disable 2MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

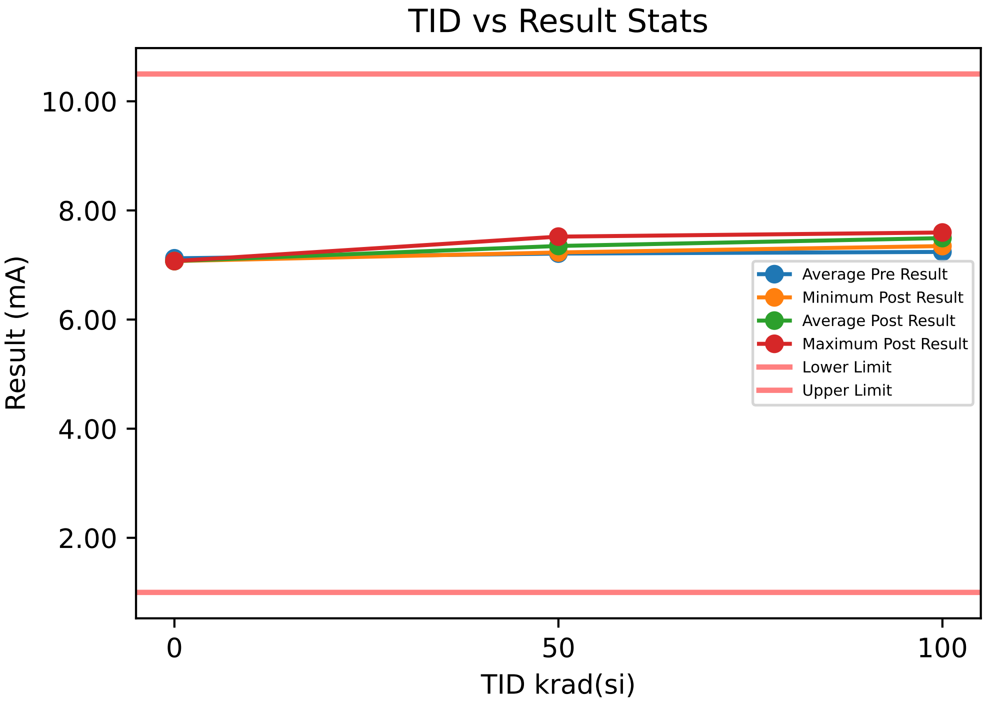
Test Results (Lower Limit = 1.0, Upper Limit = 17.0 (mA))

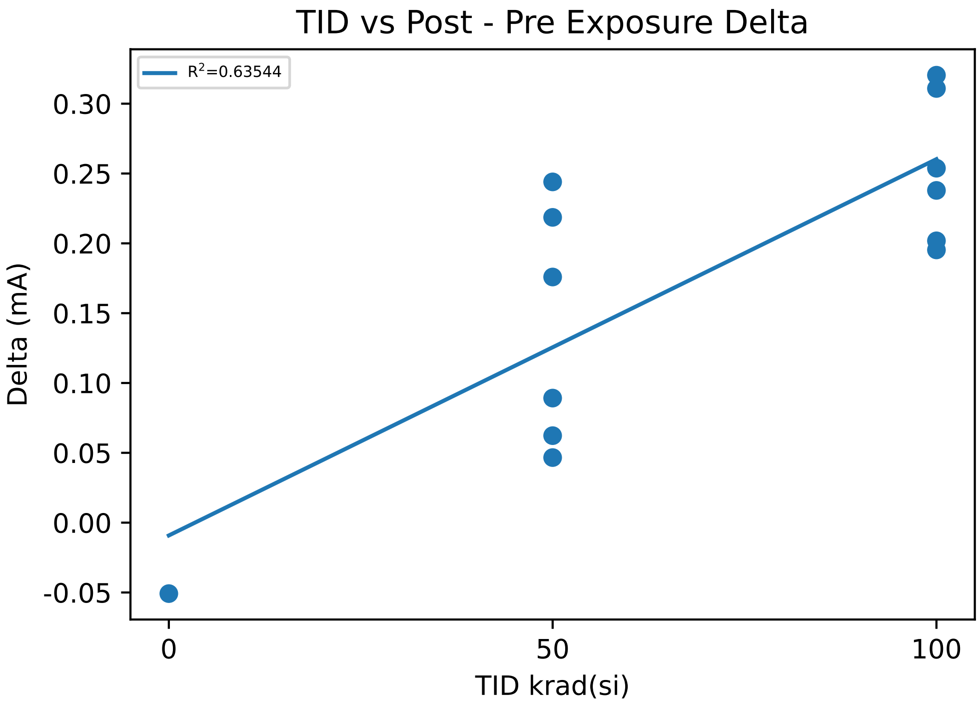
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	10.762	10.828	0.0659
60	50	Biased	10.614	10.949	0.3347
61	50	Biased	10.827	10.891	0.0644
63	100	Biased	10.879	11.126	0.2473
64	100	Biased	10.638	11	0.3623
65	100	Biased	10.808	11.12	0.3123
66	50	Unbiased	10.801	11.081	0.2801
67	50	Unbiased	10.765	10.794	0.0283
68	50	Unbiased	10.874	11.234	0.3594
69	100	Unbiased	10.969	11.223	0.2543
70	100	Unbiased	10.844	11.348	0.5044
71	100	Unbiased	10.858	10.996	0.1378
72	0	Control	10.533	10.671	0.1374

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.533	10.533	10.533		10.671	10.671	10.671		0.1374	0.1374	0.1374	
50	10.614	10.774	10.874	0.088654	10.794	10.963	11.234	0.16695	0.0283	0.1888	0.3594	0.1517
100	10.638	10.833	10.969	0.10953	10.996	11.136	11.348	0.1349	0.1378	0.30307	0.5044	0.12404

Device Test: 35.27 Iop HS BOOT IIM Interlock Disable 2MHz VIN_10V





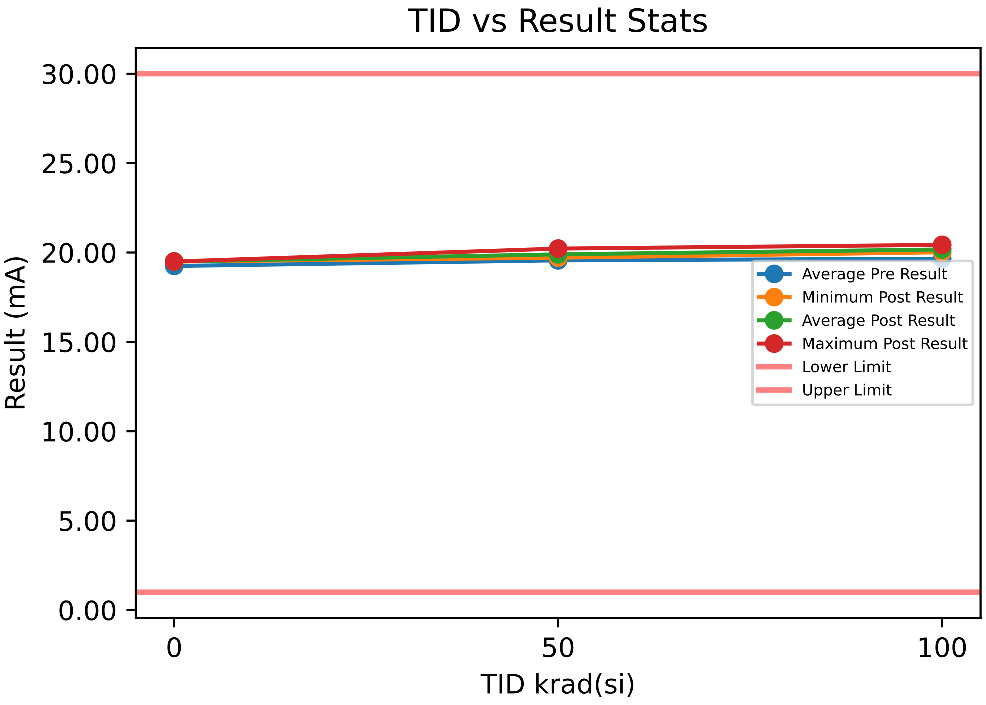
Test Results (Lower Limit = 1.0, Upper Limit = 10.5 (mA))

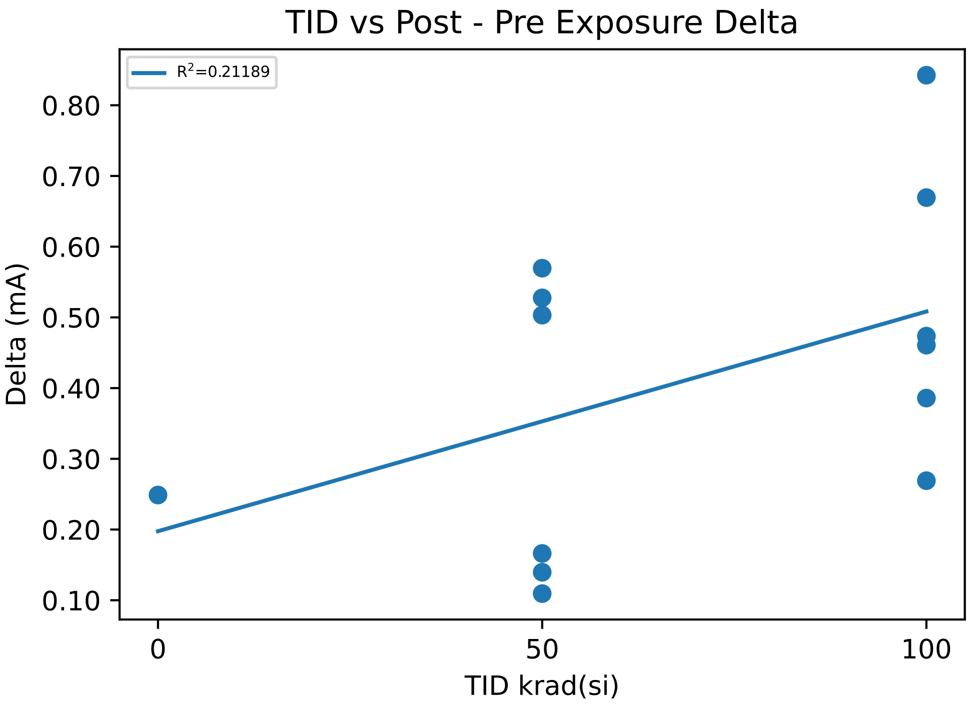
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0537	7.2296	0.1759
60	50	Biased	7.2132	7.3024	0.0892
61	50	Biased	7.0469	7.2909	0.244
63	100	Biased	7.2114	7.5223	0.3109
64	100	Biased	7.145	7.3468	0.2018
65	100	Biased	7.3465	7.5844	0.2379
66	50	Unbiased	7.4014	7.448	0.0466
67	50	Unbiased	7.3012	7.5198	0.2186
68	50	Unbiased	7.2377	7.3	0.0623
69	100	Unbiased	7.1934	7.4472	0.2538
70	100	Unbiased	7.2665	7.4618	0.1953
71	100	Unbiased	7.2751	7.5955	0.3204
72	0	Control	7.1227	7.0719	-0.0508

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1227	7.1227	7.1227		7.0719	7.0719	7.0719		-0.0508	-0.0508	-0.0508	
50	7.0469	7.209	7.4014	0.13911	7.2296	7.3484	7.5198	0.11061	0.0466	0.13943	0.244	0.084407
100	7.145	7.2397	7.3465	0.07112	7.3468	7.493	7.5955	0.093983	0.1953	0.25335	0.3204	0.053054

Device Test: 35.28 Iop LS VIN IIM Interlock Disable 5MHz VIN_10V





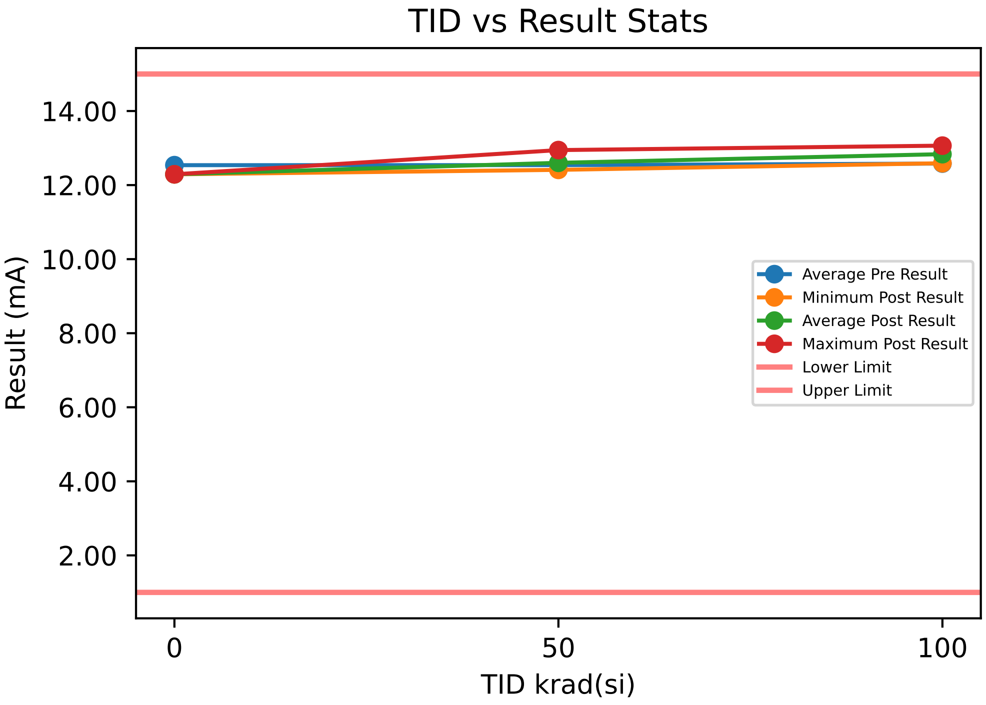
Test Results (Lower Limit = 1.0, Upper Limit = 30.0 (mA))

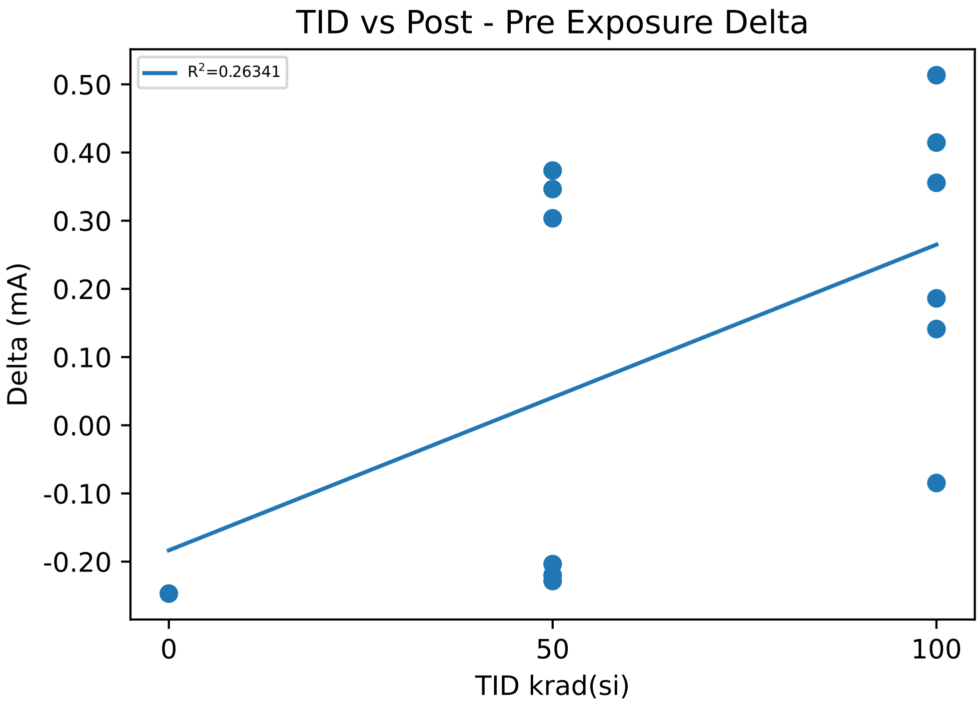
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	19.603	19.769	0.1662
60	50	Biased	19.318	19.846	0.5276
61	50	Biased	19.66	19.799	0.1396
63	100	Biased	19.719	20.105	0.3859
64	100	Biased	19.343	20.013	0.6694
65	100	Biased	19.662	20.136	0.4735
66	50	Unbiased	19.536	20.039	0.5032
67	50	Unbiased	19.599	19.708	0.1094
68	50	Unbiased	19.65	20.219	0.5696
69	100	Unbiased	19.862	20.323	0.4607
70	100	Unbiased	19.585	20.428	0.8425
71	100	Unbiased	19.756	20.025	0.2691
72	0	Control	19.247	19.496	0.2488

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.247	19.247	19.247		19.496	19.496	19.496		0.2488	0.2488	0.2488	
50	19.318	19.561	19.66	0.12686	19.708	19.897	20.219	0.19413	0.1094	0.33593	0.5696	0.21817
100	19.343	19.655	19.862	0.17852	20.013	20.172	20.428	0.1679	0.2691	0.51685	0.8425	0.20634

Device Test: 35.29 Iop HS BOOT IIM Interlock Disable 5MHz VIN_10V





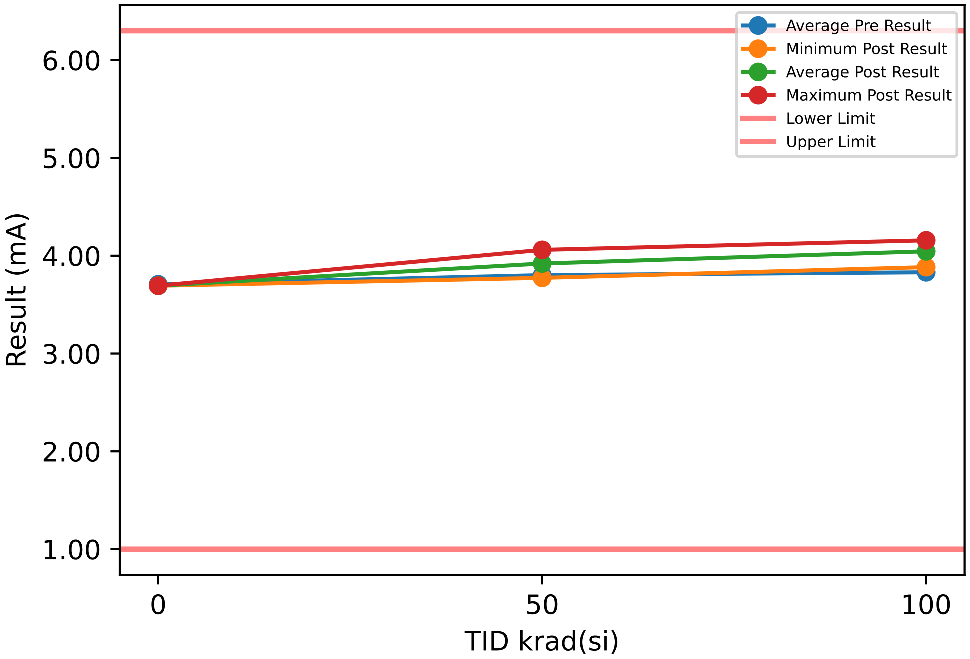
Test Results (Lower Limit = 1.0, Upper Limit = 15.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	12.287	12.59	0.3035
60	50	Biased	12.615	12.411	-0.2036
61	50	Biased	12.281	12.655	0.3735
63	100	Biased	12.532	12.947	0.4146
64	100	Biased	12.578	12.764	0.1861
65	100	Biased	12.695	12.836	0.1411
66	50	Unbiased	12.791	12.562	-0.2285
67	50	Unbiased	12.599	12.945	0.3464
68	50	Unbiased	12.664	12.444	-0.2199
69	100	Unbiased	12.453	12.808	0.3556
70	100	Unbiased	12.675	12.591	-0.0847
71	100	Unbiased	12.552	13.065	0.5134
72	0	Control	12.538	12.291	-0.2469

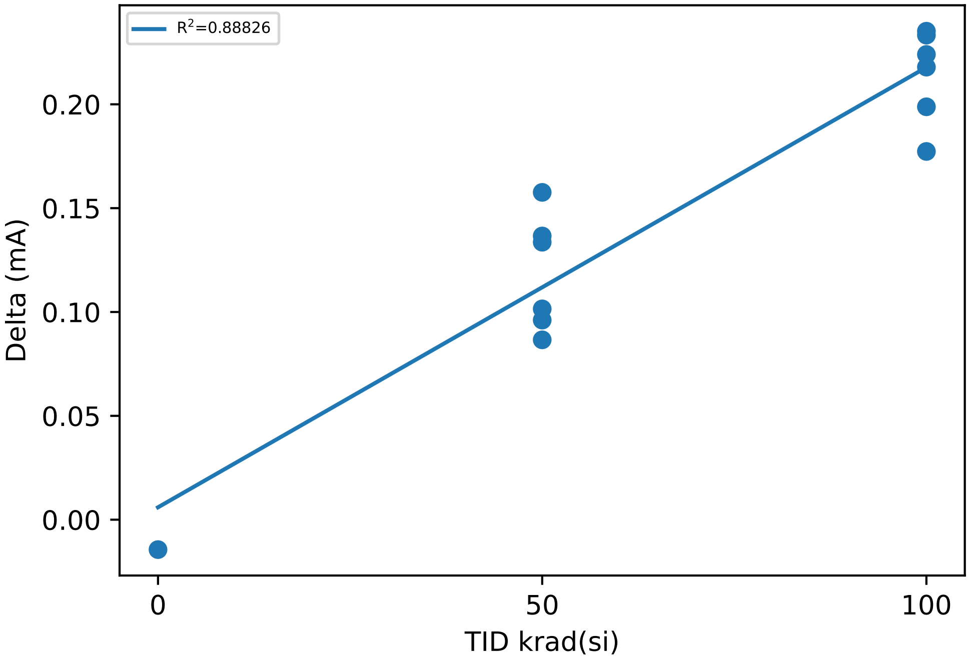
Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.538	12.538	12.538		12.291	12.291	12.291		-0.2469	-0.2469	-0.2469	
50	12.281	12.539	12.791	0.20902	12.411	12.601	12.945	0.19155	-0.2285	0.0619	0.3735	0.3068
100	12.453	12.581	12.695	0.091247	12.591	12.835	13.065	0.16186	-0.0847	0.25435	0.5134	0.21701

Device Test: 35.3 Iq HS BOOT IIM Interlock VIN_10V



TID vs Result Stats



TID vs Post - Pre Exposure Delta

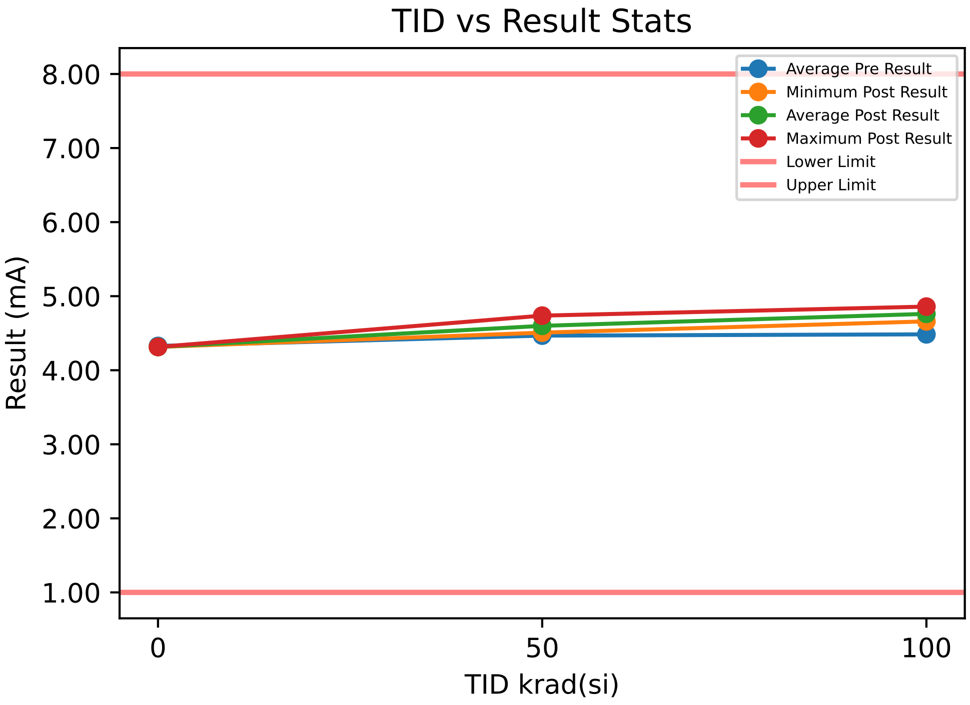
Test Results (Lower Limit = 1.0, Upper Limit = 6.3 (mA))

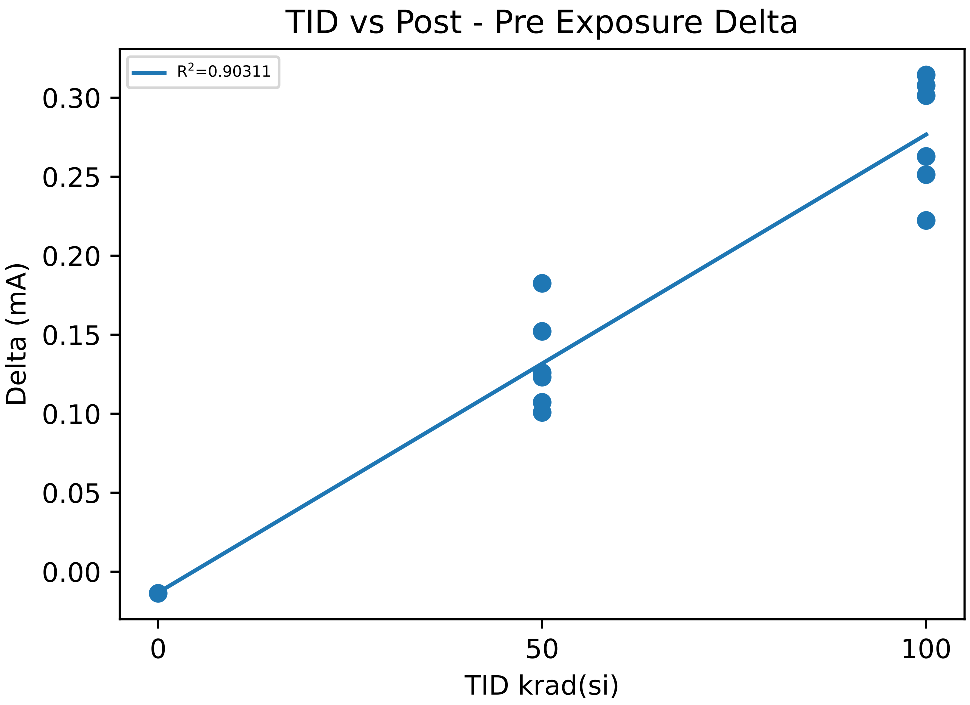
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.6774	3.7735	0.0961
60	50	Biased	3.7926	3.9262	0.1336
61	50	Biased	3.6655	3.8231	0.1576
63	100	Biased	3.8158	4.0491	0.2333
64	100	Biased	3.706	3.8833	0.1773
65	100	Biased	3.9333	4.1573	0.224
66	50	Unbiased	3.9734	4.06	0.0866
67	50	Unbiased	3.9092	4.0458	0.1366
68	50	Unbiased	3.7916	3.8931	0.1015
69	100	Unbiased	3.7987	3.9975	0.1988
70	100	Unbiased	3.8472	4.0824	0.2352
71	100	Unbiased	3.8833	4.1012	0.2179
72	0	Control	3.7078	3.6934	-0.0144

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7078	3.7078	3.7078		3.6934	3.6934	3.6934		-0.0144	-0.0144	-0.0144	
50	3.6655	3.8016	3.9734	0.12266	3.7735	3.9203	4.06	0.11579	0.0866	0.11867	0.1576	0.027902
100	3.706	3.8307	3.9333	0.077925	3.8833	4.0451	4.1573	0.095486	0.1773	0.21442	0.2352	0.022423

Device Test: 35.4 Iq LS VIN IIM Interlock Disable VIN_10V





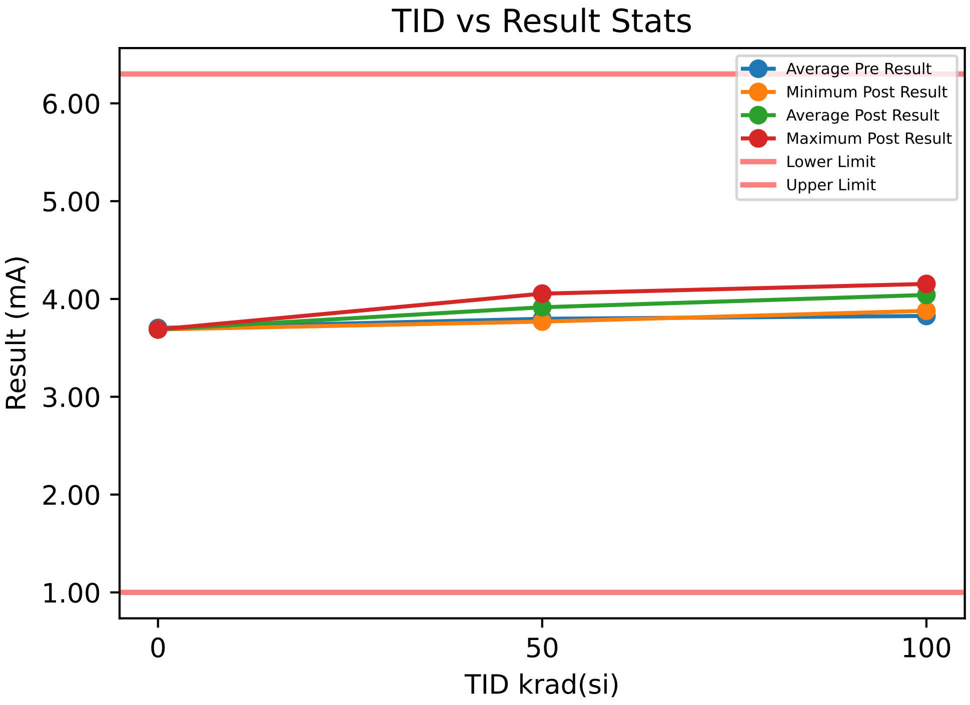
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

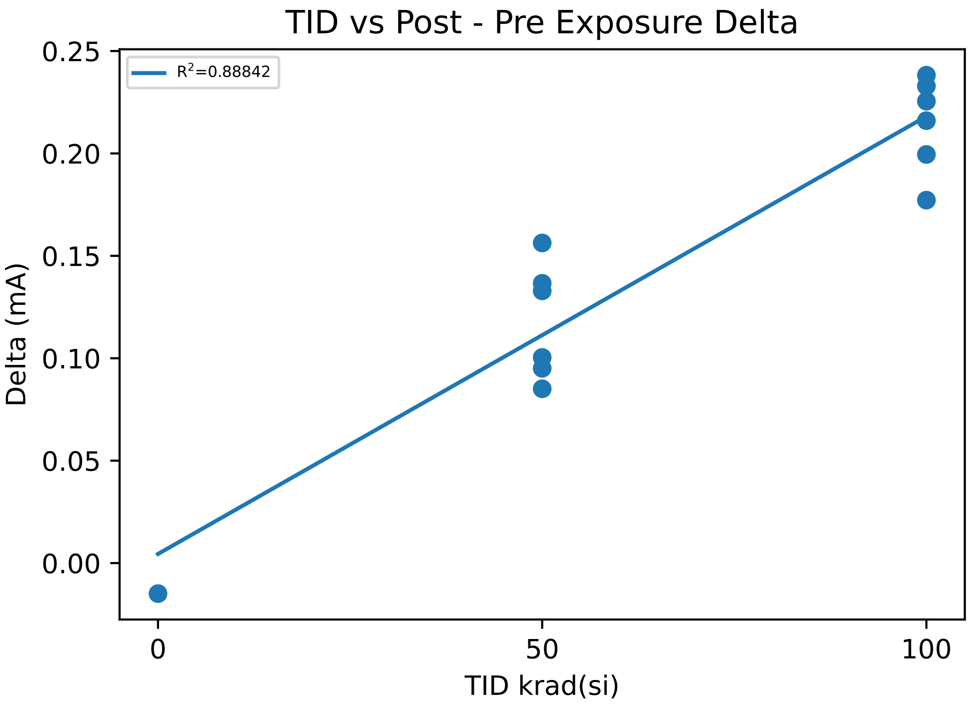
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.4387	4.5646	0.1259
60	50	Biased	4.4391	4.5912	0.1521
61	50	Biased	4.4885	4.6116	0.1231
63	100	Biased	4.4885	4.8029	0.3144
64	100	Biased	4.4429	4.7057	0.2628
65	100	Biased	4.4291	4.6804	0.2513
66	50	Unbiased	4.476	4.5832	0.1072
67	50	Unbiased	4.4067	4.5075	0.1008
68	50	Unbiased	4.5548	4.7373	0.1825
69	100	Unbiased	4.5513	4.859	0.3077
70	100	Unbiased	4.5578	4.8591	0.3013
71	100	Unbiased	4.4372	4.6595	0.2223
72	0	Control	4.3279	4.3142	-0.0137

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3279	4.3279	4.3279		4.3142	4.3142	4.3142		-0.0137	-0.0137	-0.0137	
50	4.4067	4.4673	4.5548	0.051898	4.5075	4.5992	4.7373	0.076356	0.1008	0.13193	0.1825	0.030526
100	4.4291	4.4845	4.5578	0.058117	4.6595	4.7611	4.8591	0.090377	0.2223	0.27663	0.3144	0.036838

Device Test: 35.5 Iq HS BOOT IIM Interlock Disable VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

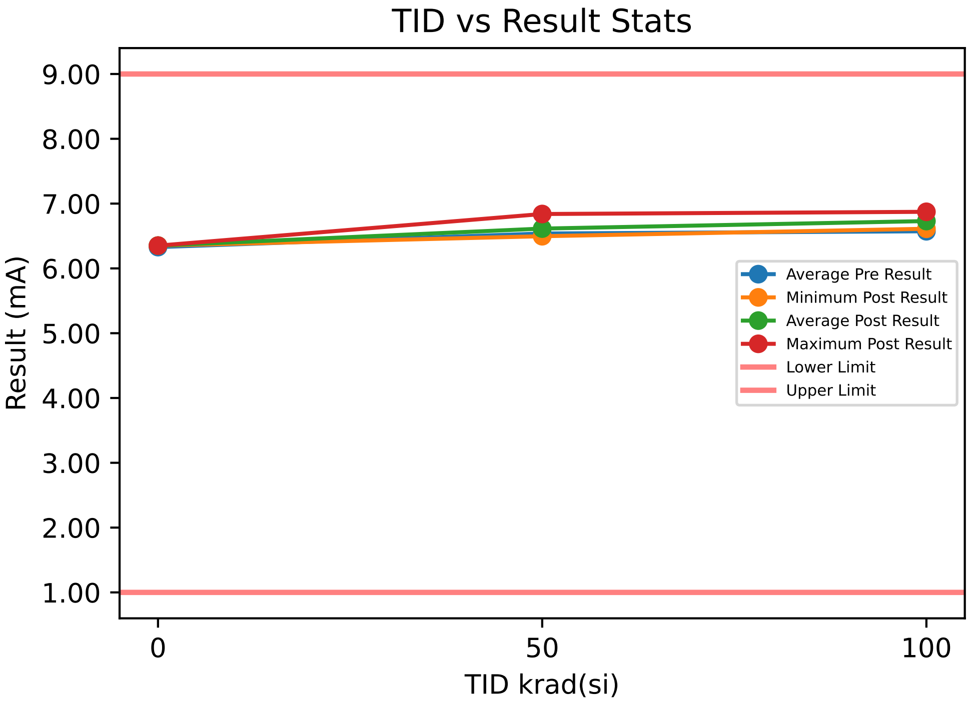
Test Results (Lower Limit = 1.0, Upper Limit = 6.3 (mA))

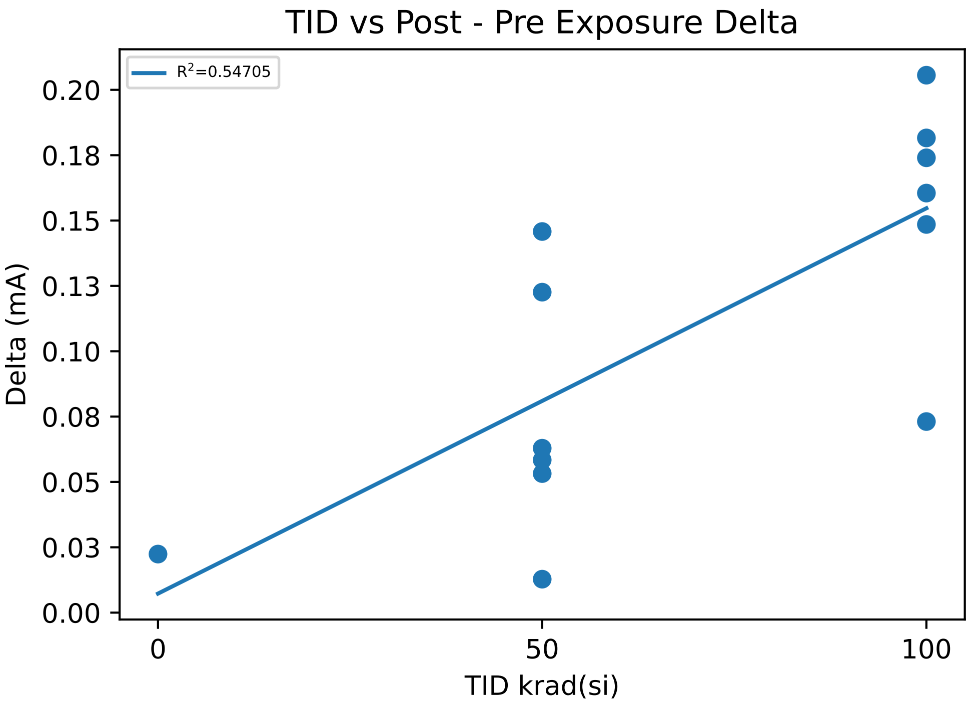
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.6735	3.7686	0.0951
60	50	Biased	3.7878	3.9207	0.1329
61	50	Biased	3.661	3.8173	0.1563
63	100	Biased	3.8114	4.0443	0.2329
64	100	Biased	3.7016	3.8788	0.1772
65	100	Biased	3.9283	4.1538	0.2255
66	50	Unbiased	3.9692	4.0543	0.0851
67	50	Unbiased	3.9048	4.0414	0.1366
68	50	Unbiased	3.7877	3.8881	0.1004
69	100	Unbiased	3.7941	3.9936	0.1995
70	100	Unbiased	3.8424	4.0806	0.2382
71	100	Unbiased	3.8799	4.0959	0.216
72	0	Control	3.7034	3.6885	-0.0149

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7034	3.7034	3.7034		3.6885	3.6885	3.6885		-0.0149	-0.0149	-0.0149	
50	3.661	3.7973	3.9692	0.12263	3.7686	3.9151	4.0543	0.11586	0.0851	0.11773	0.1563	0.028111
100	3.7016	3.8263	3.9283	0.077904	3.8788	4.0412	4.1538	0.095783	0.1772	0.21488	0.2382	0.022973

Device Test: 35.6 Iop LS VIN PWM 500kHz VIN_10V





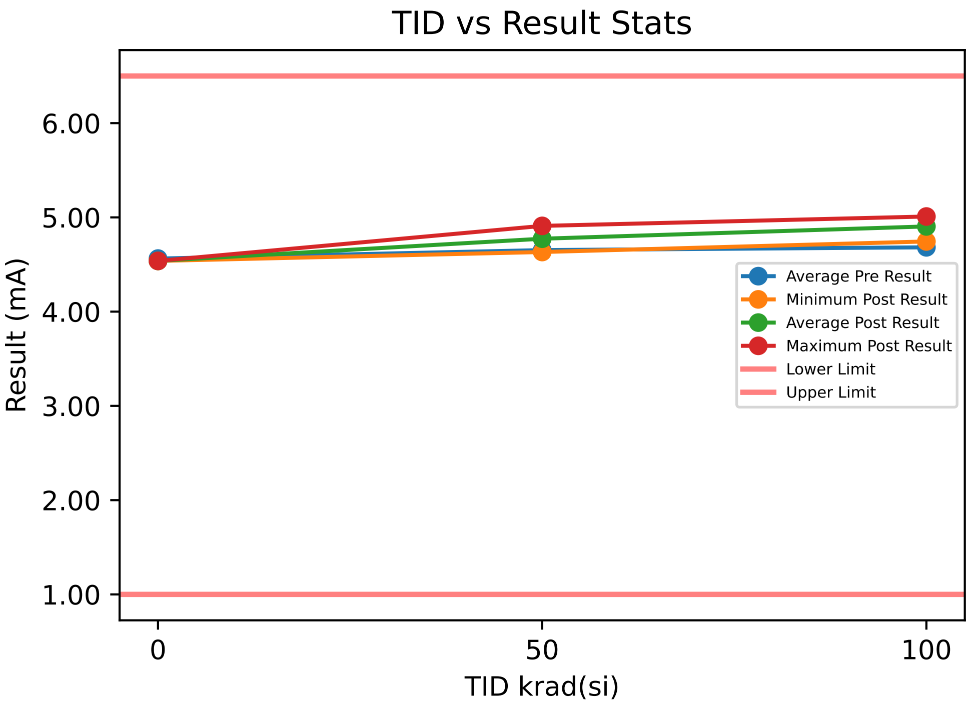
Test Results (Lower Limit = 1.0, Upper Limit = 9.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.4453	6.5037	0.0584
60	50	Biased	6.4162	6.5388	0.1226
61	50	Biased	6.538	6.5912	0.0532
63	100	Biased	6.6202	6.7942	0.174
64	100	Biased	6.4302	6.6118	0.1816
65	100	Biased	6.5137	6.6622	0.1485
66	50	Unbiased	6.6542	6.7171	0.0629
67	50	Unbiased	6.4836	6.4964	0.0128
68	50	Unbiased	6.6936	6.8394	0.1458
69	100	Unbiased	6.6554	6.8159	0.1605
70	100	Unbiased	6.6677	6.8733	0.2056
71	100	Unbiased	6.5513	6.6244	0.0731
72	0	Control	6.3289	6.3513	0.0224

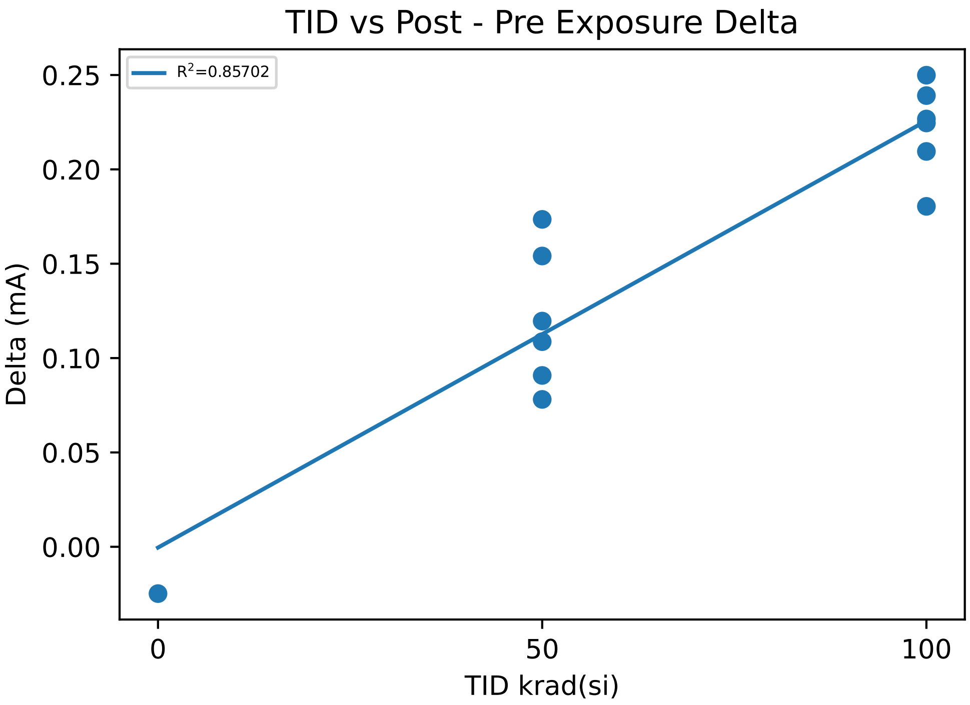
Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.3289	6.3289	6.3289		6.3513	6.3513	6.3513		0.0224	0.0224	0.0224	
50	6.4162	6.5385	6.6936	0.11323	6.4964	6.6144	6.8394	0.13682	0.0128	0.07595	0.1458	0.049069
100	6.4302	6.5731	6.6677	0.092049	6.6118	6.7303	6.8733	0.11113	0.0731	0.15722	0.2056	0.045562

Device Test: 35.7 Iop HS BOOT PWM 500kHz VIN_10V



TID vs Result Stats



TID vs Post - Pre Exposure Delta

Test Results (Lower Limit = 1.0, Upper Limit = 6.5 (mA))

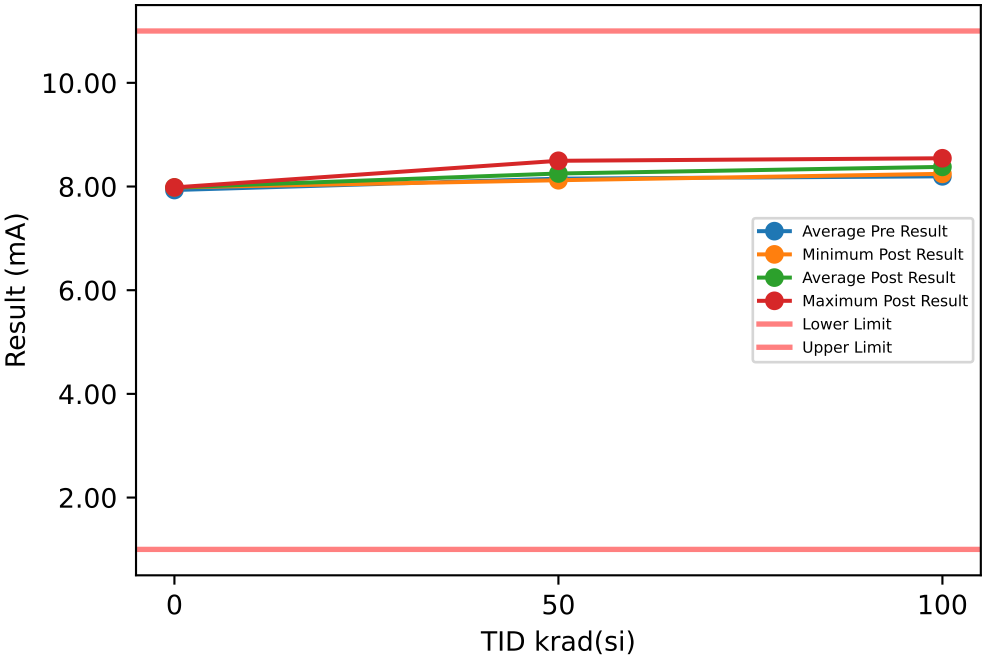
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.5239	4.6326	0.1087
60	50	Biased	4.6463	4.7659	0.1196
61	50	Biased	4.5115	4.685	0.1735
63	100	Biased	4.6639	4.9138	0.2499
64	100	Biased	4.5642	4.7446	0.1804
65	100	Biased	4.7846	5.0092	0.2246
66	50	Unbiased	4.8278	4.9059	0.0781
67	50	Unbiased	4.7556	4.9097	0.1541
68	50	Unbiased	4.6523	4.7431	0.0908
69	100	Unbiased	4.6473	4.8568	0.2095
70	100	Unbiased	4.7011	4.9278	0.2267
71	100	Unbiased	4.7325	4.9716	0.2391
72	0	Control	4.563	4.5382	-0.0248

Test Statistics (mA)

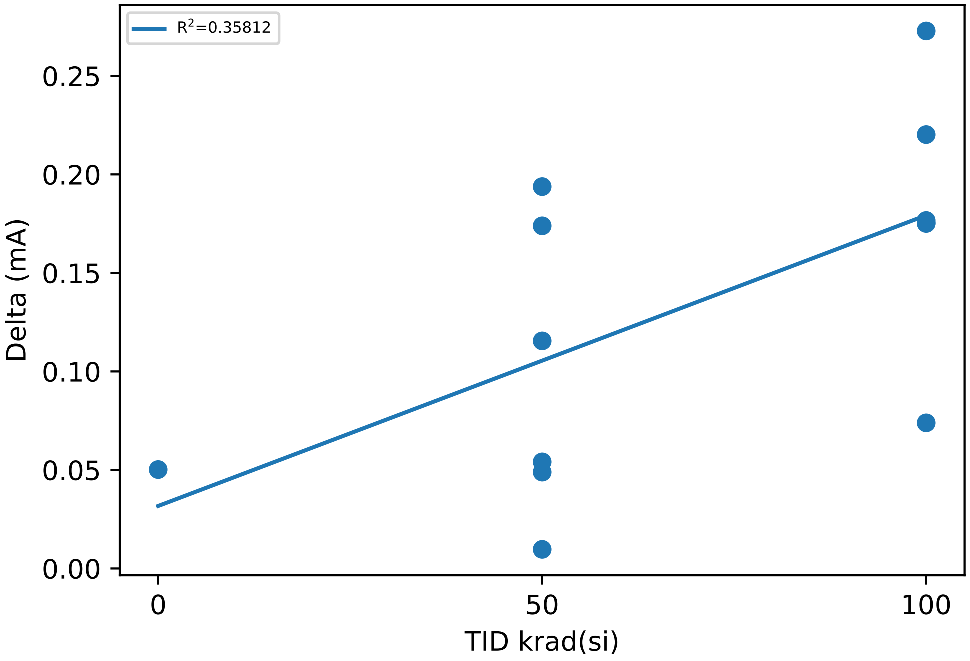
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.563	4.563	4.563		4.5382	4.5382	4.5382		-0.0248	-0.0248	-0.0248	
50	4.5115	4.6529	4.8278	0.12475	4.6326	4.7737	4.9097	0.1138	0.0781	0.1208	0.1735	0.036762
100	4.5642	4.6823	4.7846	0.07596	4.7446	4.904	5.0092	0.09374	0.1804	0.2217	0.2499	0.024437

Device Test: 35.8 Iop LS VIN PWM 1MHz VIN_10V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



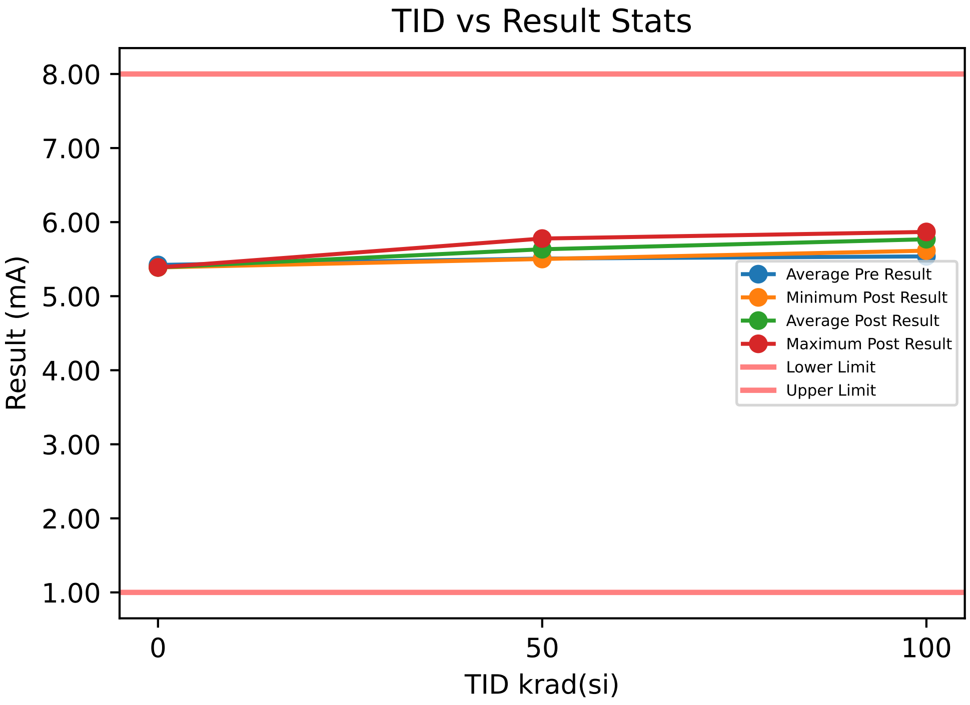
Test Results (Lower Limit = 1.0,
Upper Limit = 11.0 (mA))

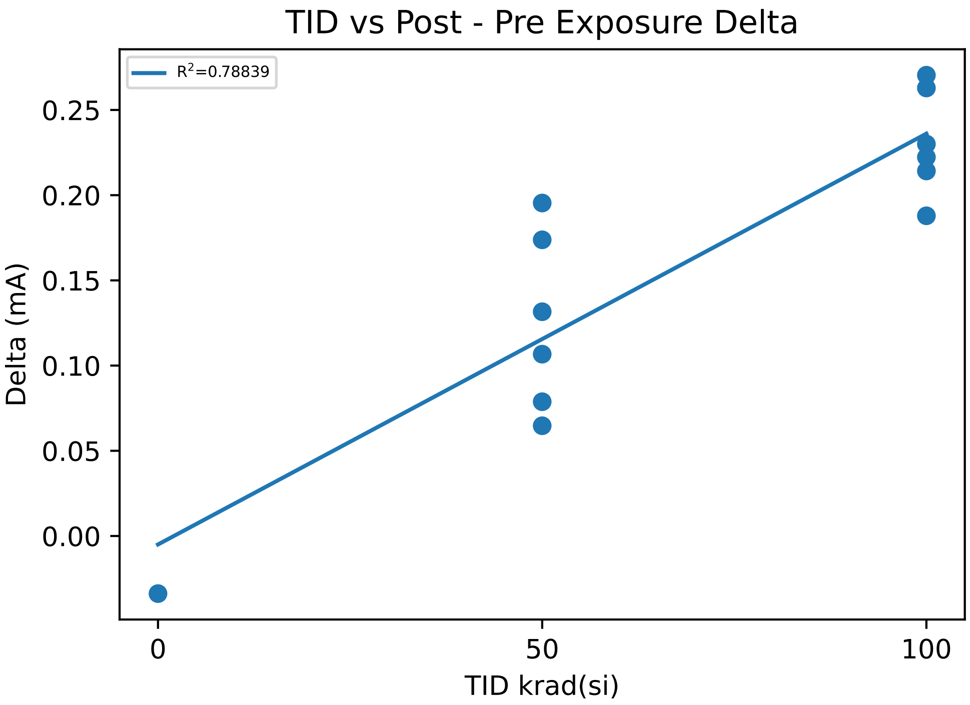
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	8.0714	8.1255	0.0541
60	50	Biased	8.0082	8.1821	0.1739
61	50	Biased	8.1637	8.2126	0.0489
63	100	Biased	8.2487	8.424	0.1753
64	100	Biased	8.0248	8.245	0.2202
65	100	Biased	8.1458	8.3224	0.1766
66	50	Unbiased	8.2523	8.3678	0.1155
67	50	Unbiased	8.1114	8.1211	0.0097
68	50	Unbiased	8.3025	8.4963	0.1938
69	100	Unbiased	8.2963	8.4714	0.1751
70	100	Unbiased	8.2723	8.5451	0.2728
71	100	Unbiased	8.1916	8.2655	0.0739
72	0	Control	7.9324	7.9826	0.0502

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.9324	7.9324	7.9324		7.9826	7.9826	7.9826		0.0502	0.0502	0.0502	
50	8.0082	8.1516	8.3025	0.11106	8.1211	8.2509	8.4963	0.15011	0.0097	0.099317	0.1938	0.073985
100	8.0248	8.1966	8.2963	0.1005	8.245	8.3789	8.5451	0.12016	0.0739	0.18232	0.2728	0.06559

Device Test: 35.9 Iop HS BOOT PWM 1MHz VIN_10V





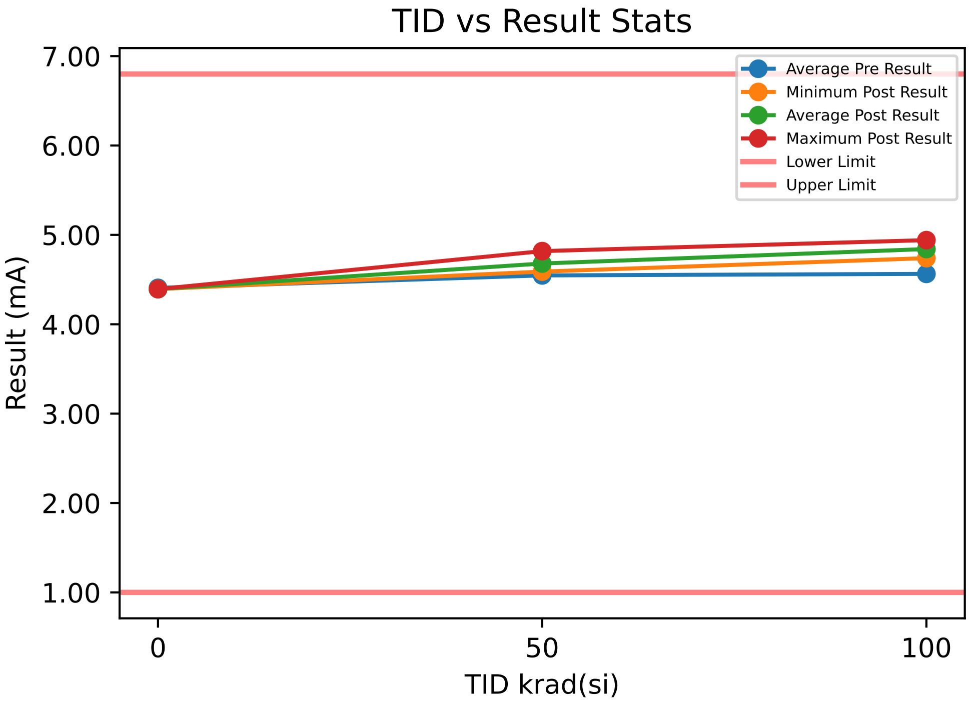
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

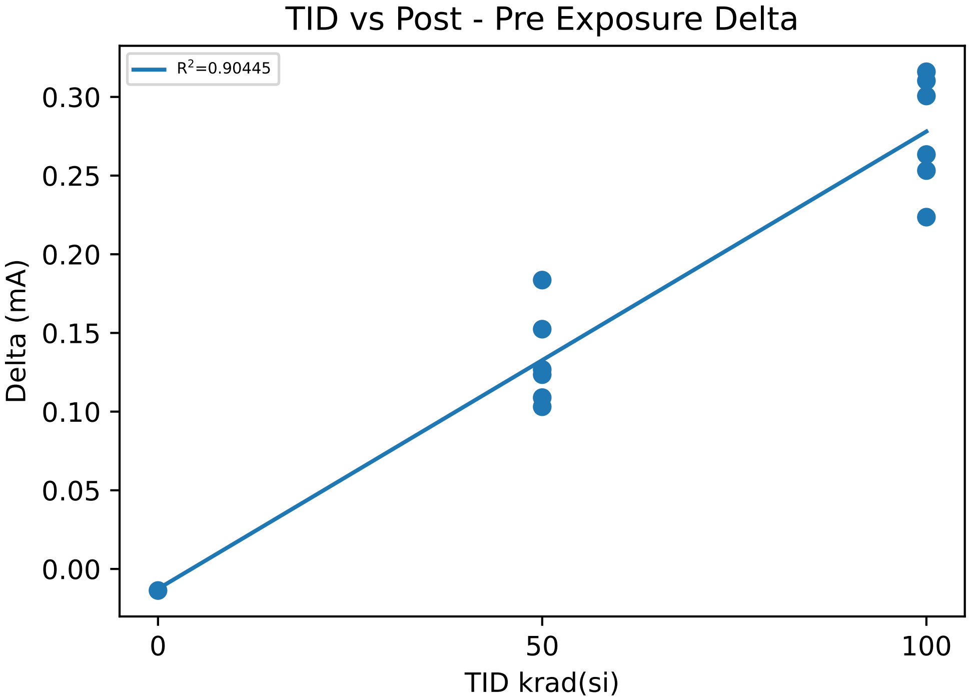
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.37	5.5016	0.1316
60	50	Biased	5.5047	5.6114	0.1067
61	50	Biased	5.3599	5.5553	0.1954
63	100	Biased	5.5145	5.7849	0.2704
64	100	Biased	5.4265	5.6144	0.1879
65	100	Biased	5.6374	5.8674	0.23
66	50	Unbiased	5.6904	5.7551	0.0647
67	50	Unbiased	5.6043	5.7781	0.1738
68	50	Unbiased	5.5185	5.5973	0.0788
69	100	Unbiased	5.5	5.7223	0.2223
70	100	Unbiased	5.5609	5.7751	0.2142
71	100	Unbiased	5.5832	5.8461	0.2629
72	0	Control	5.4218	5.388	-0.0338

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4218	5.4218	5.4218		5.388	5.388	5.388		-0.0338	-0.0338	-0.0338	
50	5.3599	5.508	5.6904	0.12934	5.5016	5.6331	5.7781	0.11046	0.0647	0.12517	0.1954	0.051935
100	5.4265	5.5371	5.6374	0.073309	5.6144	5.7684	5.8674	0.091648	0.1879	0.23128	0.2704	0.030939

Device Test: 36.0 Iq LS VIN PWM VIN_12V





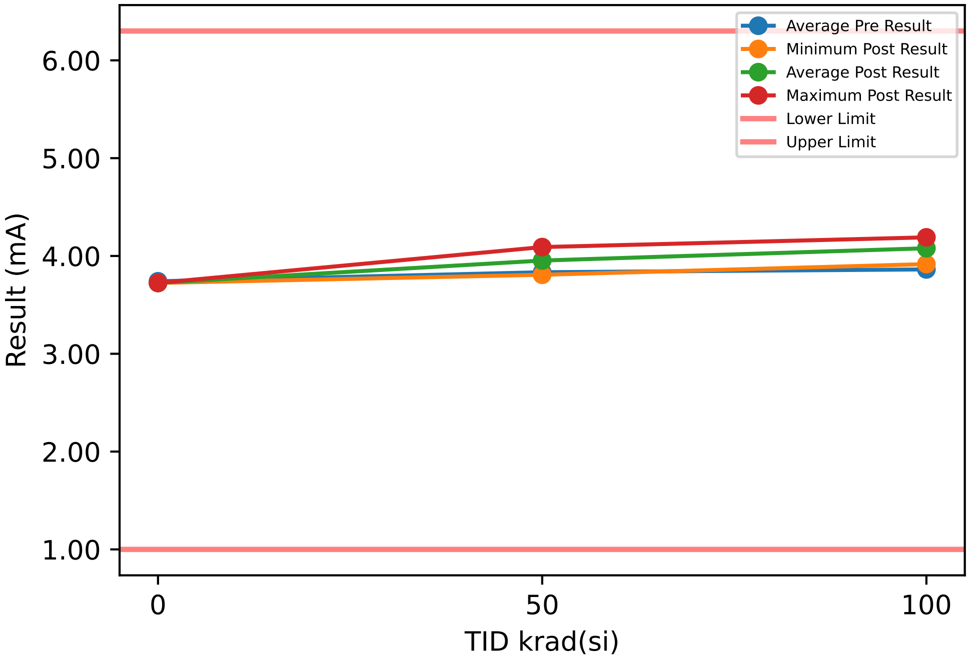
Test Results (Lower Limit = 1.0, Upper Limit = 6.8 (mA))

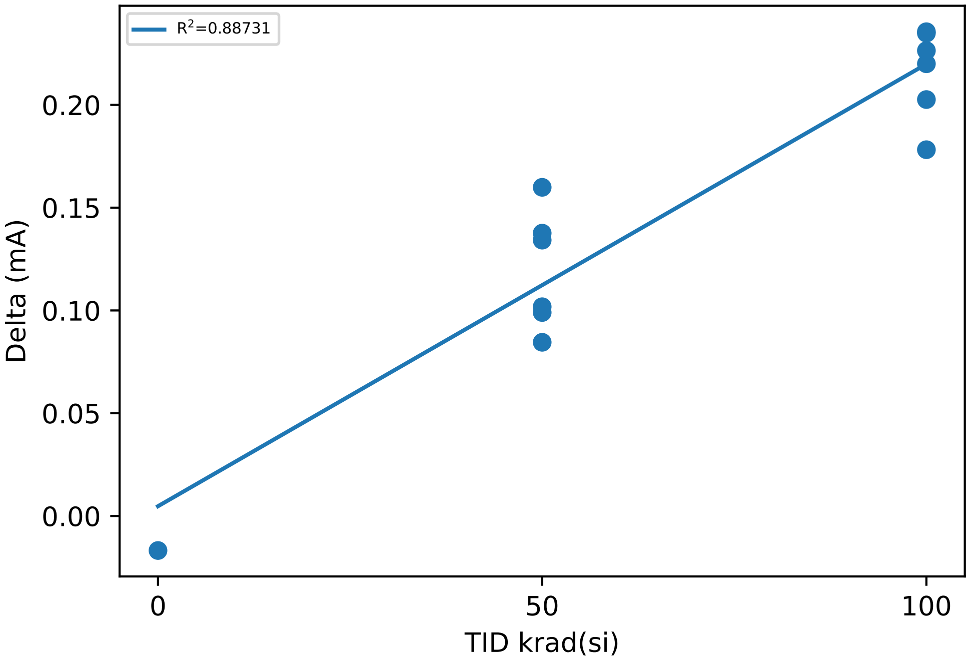
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.5167	4.6435	0.1268
60	50	Biased	4.5183	4.6707	0.1524
61	50	Biased	4.5688	4.6923	0.1235
63	100	Biased	4.5681	4.8841	0.316
64	100	Biased	4.522	4.7854	0.2634
65	100	Biased	4.5073	4.7605	0.2532
66	50	Unbiased	4.5552	4.6641	0.1089
67	50	Unbiased	4.4861	4.5892	0.1031
68	50	Unbiased	4.6347	4.8183	0.1836
69	100	Unbiased	4.6309	4.9412	0.3103
70	100	Unbiased	4.6378	4.9384	0.3006
71	100	Unbiased	4.5162	4.7398	0.2236
72	0	Control	4.4072	4.3935	-0.0137

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4072	4.4072	4.4072		4.3935	4.3935	4.3935		-0.0137	-0.0137	-0.0137	
50	4.4861	4.5466	4.6347	0.052314	4.5892	4.6797	4.8183	0.076412	0.1031	0.13305	0.1836	0.030134
100	4.5073	4.5637	4.6378	0.058655	4.7398	4.8416	4.9412	0.09077	0.2236	0.27785	0.316	0.036839

Device Test: 36.1 Iq HS BOOT PWM VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

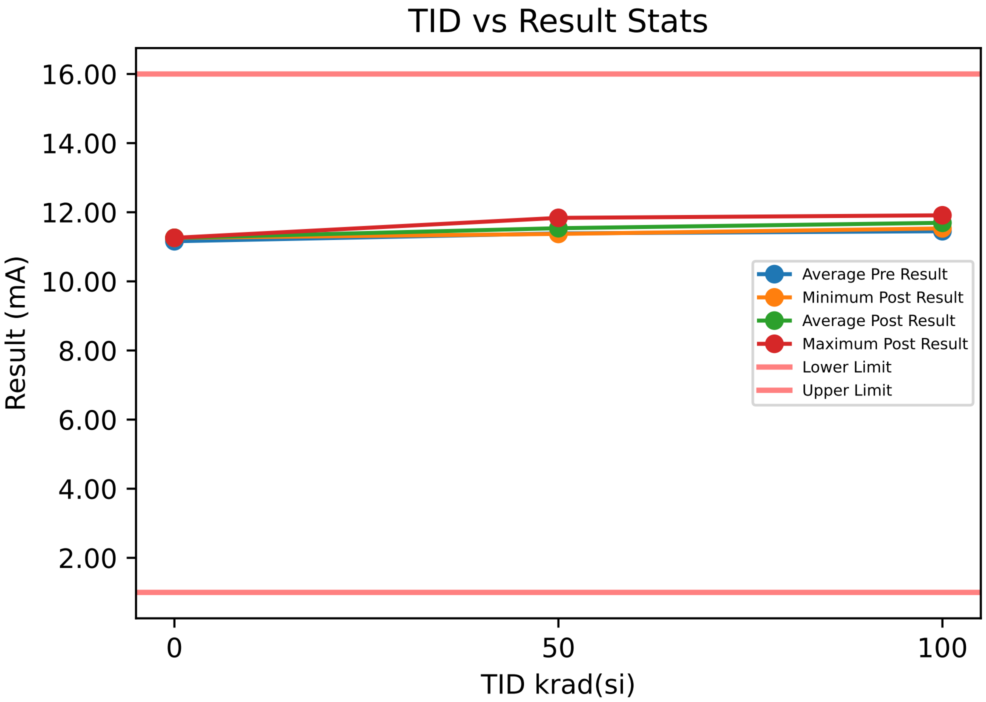
Test Results (Lower Limit = 1.0, Upper Limit = 6.3 (mA))

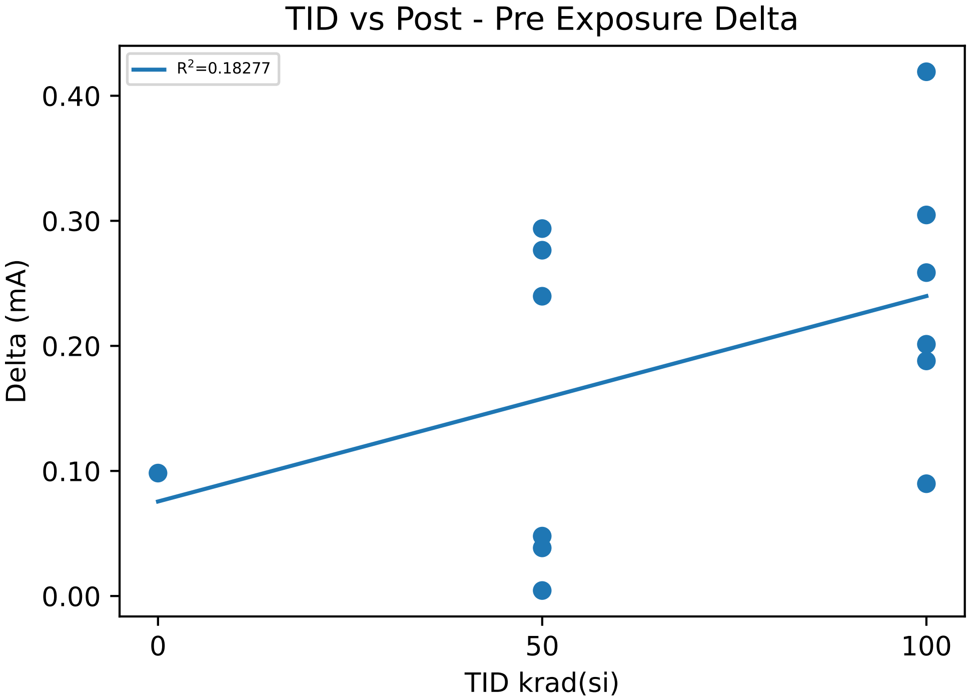
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.7086	3.8076	0.099
60	50	Biased	3.8252	3.9594	0.1342
61	50	Biased	3.6957	3.8556	0.1599
63	100	Biased	3.8477	4.0826	0.2349
64	100	Biased	3.7385	3.9167	0.1782
65	100	Biased	3.9639	4.1903	0.2264
66	50	Unbiased	4.0064	4.0909	0.0845
67	50	Unbiased	3.9406	4.0782	0.1376
68	50	Unbiased	3.8251	3.9269	0.1018
69	100	Unbiased	3.8298	4.0324	0.2026
70	100	Unbiased	3.8811	4.1167	0.2356
71	100	Unbiased	3.9143	4.1343	0.22
72	0	Control	3.7411	3.7243	-0.0168

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7411	3.7411	3.7411		3.7243	3.7243	3.7243		-0.0168	-0.0168	-0.0168	
50	3.6957	3.8336	4.0064	0.12336	3.8076	3.9531	4.0909	0.11493	0.0845	0.1195	0.1599	0.028756
100	3.7385	3.8626	3.9639	0.077428	3.9167	4.0788	4.1903	0.095281	0.1782	0.21628	0.2356	0.022242

Device Test: 36.10 Iop LS VIN PWM 2MHz VIN_12V





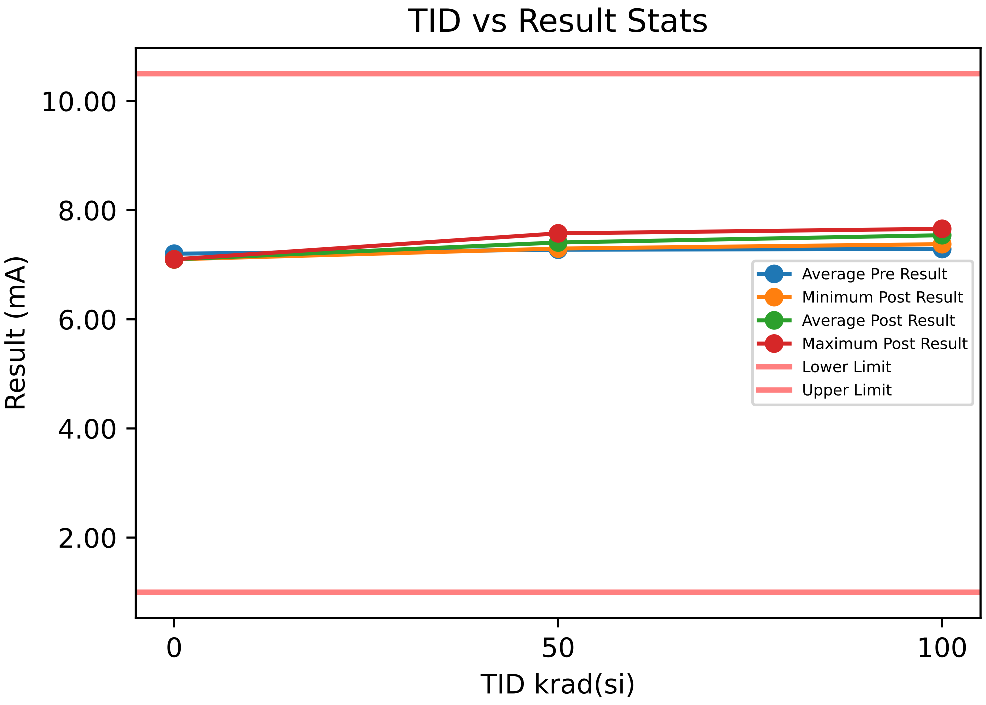
Test Results (Lower Limit = 1.0, Upper Limit = 16.0 (mA))

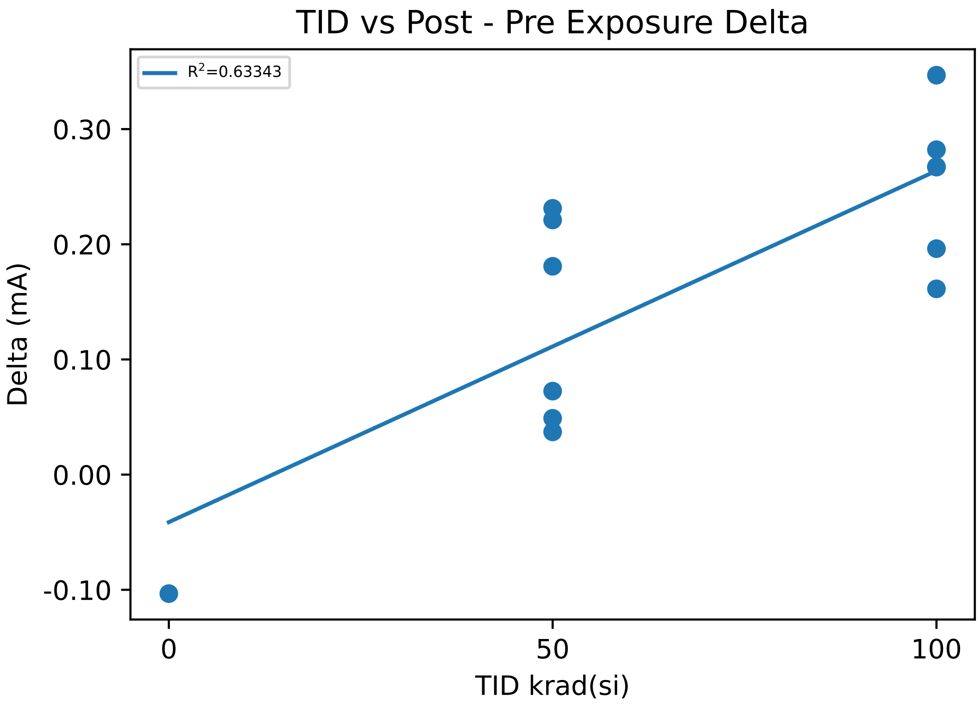
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	11.331	11.379	0.0479
60	50	Biased	11.216	11.493	0.2765
61	50	Biased	11.418	11.457	0.0385
63	100	Biased	11.508	11.696	0.188
64	100	Biased	11.228	11.532	0.3047
65	100	Biased	11.41	11.669	0.2586
66	50	Unbiased	11.45	11.69	0.2397
67	50	Unbiased	11.368	11.373	0.0044
68	50	Unbiased	11.543	11.837	0.2938
69	100	Unbiased	11.585	11.787	0.2013
70	100	Unbiased	11.492	11.911	0.4192
71	100	Unbiased	11.48	11.57	0.0898
72	0	Control	11.16	11.259	0.0983

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.16	11.16	11.16		11.259	11.259	11.259		0.0983	0.0983	0.0983	
50	11.216	11.388	11.543	0.11145	11.373	11.538	11.837	0.18649	0.0044	0.15013	0.2938	0.13325
100	11.228	11.451	11.585	0.12284	11.532	11.694	11.911	0.13996	0.0898	0.2436	0.4192	0.11254

Device Test: 36.11 Iop HS BOOT PWM 2MHz VIN_12V





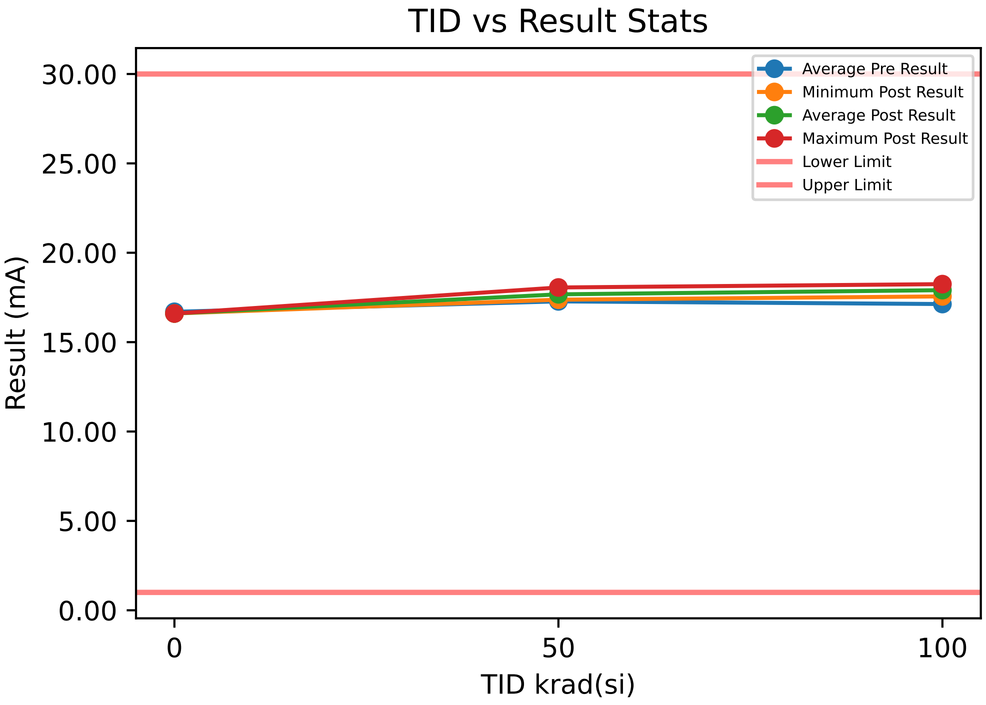
Test Results (Lower Limit = 1.0, Upper Limit = 10.5 (mA))

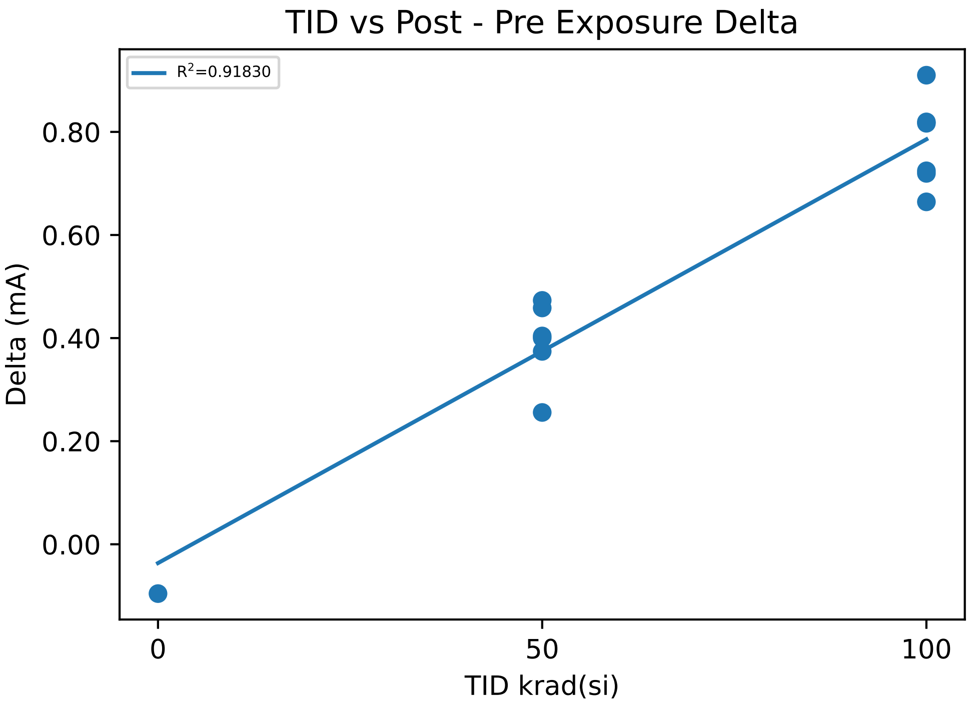
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.1157	7.2966	0.1809
60	50	Biased	7.2832	7.3557	0.0725
61	50	Biased	7.115	7.3462	0.2312
63	100	Biased	7.2716	7.5537	0.2821
64	100	Biased	7.2158	7.3771	0.1613
65	100	Biased	7.3692	7.6366	0.2674
66	50	Unbiased	7.4739	7.511	0.0371
67	50	Unbiased	7.3539	7.575	0.2211
68	50	Unbiased	7.312	7.3609	0.0489
69	100	Unbiased	7.2296	7.4966	0.267
70	100	Unbiased	7.3288	7.525	0.1962
71	100	Unbiased	7.3117	7.6585	0.3468
72	0	Control	7.2021	7.0988	-0.1033

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2021	7.2021	7.2021		7.0988	7.0988	7.0988		-0.1033	-0.1033	-0.1033	
50	7.115	7.2756	7.4739	0.14014	7.2966	7.4076	7.575	0.10925	0.0371	0.13195	0.2312	0.08902
100	7.2158	7.2878	7.3692	0.059518	7.3771	7.5413	7.6585	0.10217	0.1613	0.25347	0.3468	0.065852

Device Test: 36.12 Iop LS VIN PWM 5MHz VIN_12V





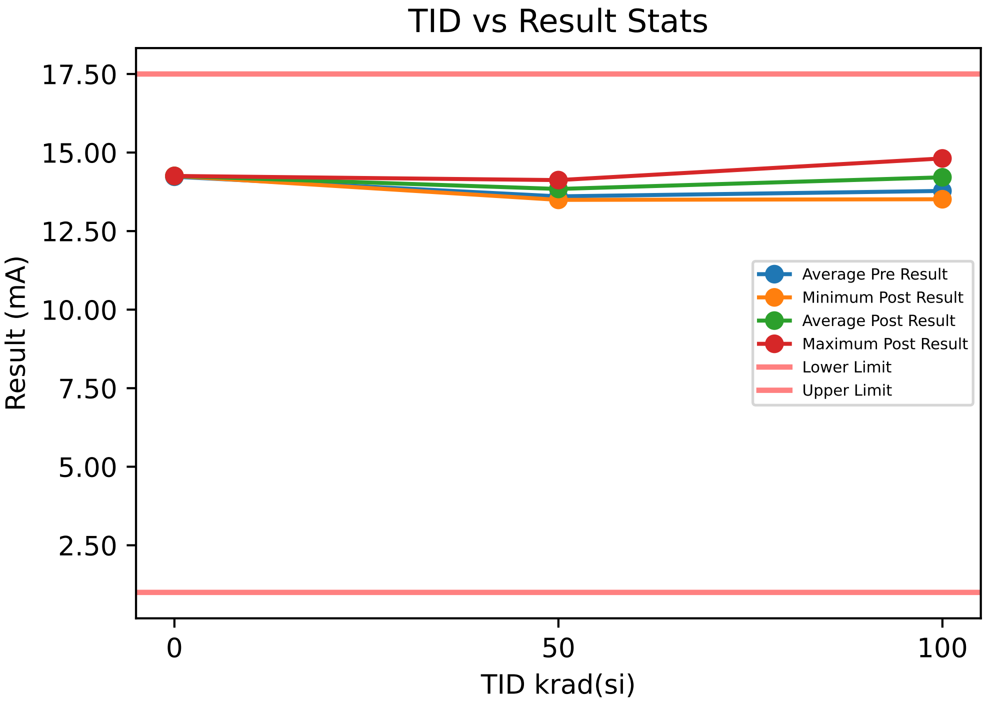
Test Results (Lower Limit = 1.0, Upper Limit = 30.0 (mA))

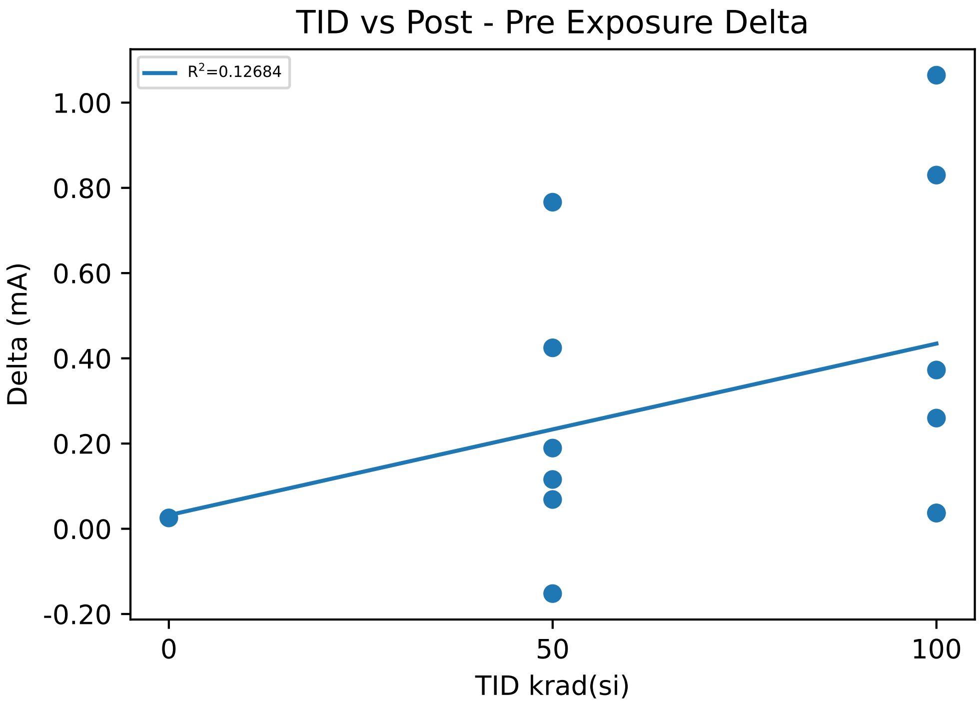
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	17.26	17.664	0.4041
60	50	Biased	17.204	17.604	0.4001
61	50	Biased	17.164	17.623	0.4585
63	100	Biased	17.299	18.116	0.8167
64	100	Biased	16.921	17.64	0.7195
65	100	Biased	17.099	17.763	0.6643
66	50	Unbiased	17.465	17.721	0.2557
67	50	Unbiased	16.902	17.375	0.4731
68	50	Unbiased	17.684	18.058	0.3742
69	100	Unbiased	17.335	18.245	0.91
70	100	Unbiased	17.398	18.122	0.7245
71	100	Unbiased	16.739	17.558	0.8194
72	0	Control	16.698	16.602	-0.0957

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	16.698	16.698	16.698		16.602	16.602	16.602		-0.0957	-0.0957	-0.0957	
50	16.902	17.28	17.684	0.26814	17.375	17.674	18.058	0.22199	0.2557	0.39428	0.4731	0.077556
100	16.739	17.132	17.398	0.26084	17.558	17.907	18.245	0.28903	0.6643	0.77573	0.91	0.089238

Device Test: 36.13 Iop HS BOOT PWM 5MHz VIN_12V





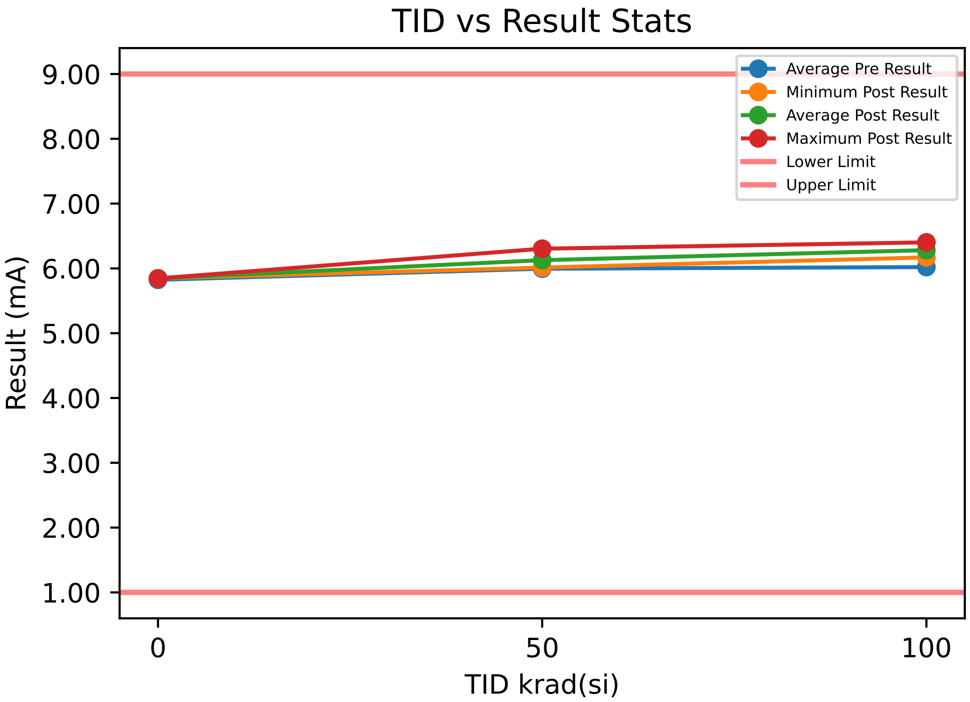
Test Results (Lower Limit = 1.0, Upper Limit = 17.5 (mA))

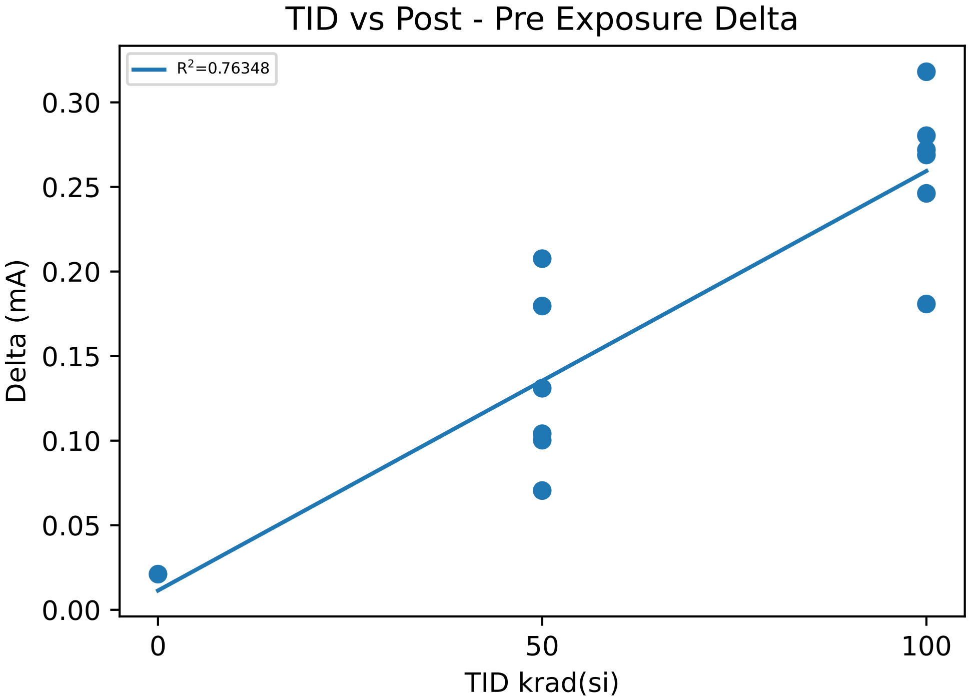
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	13.5	13.69	0.1894
60	50	Biased	13.698	14.123	0.4246
61	50	Biased	13.329	14.095	0.7664
63	100	Biased	13.983	14.813	0.83
64	100	Biased	13.575	14.64	1.0644
65	100	Biased	14.236	14.273	0.0367
66	50	Unbiased	13.425	13.494	0.0687
67	50	Unbiased	14.238	14.086	-0.1521
68	50	Unbiased	13.442	13.558	0.1157
69	100	Unbiased	13.271	13.644	0.3726
70	100	Unbiased	13.476	13.514	0.0373
71	100	Unbiased	14.127	14.386	0.2598
72	0	Control	14.23	14.255	0.0255

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	14.23	14.23	14.23		14.255	14.255	14.255		0.0255	0.0255	0.0255	
50	13.329	13.605	14.238	0.33335	13.494	13.841	14.123	0.29262	-0.1521	0.23545	0.7664	0.32005
100	13.271	13.778	14.236	0.39042	13.514	14.212	14.813	0.52696	0.0367	0.43347	1.0644	0.4251

Device Test: 36.14 Iop LS VIN IIM Interlock 500kHz VIN_12V





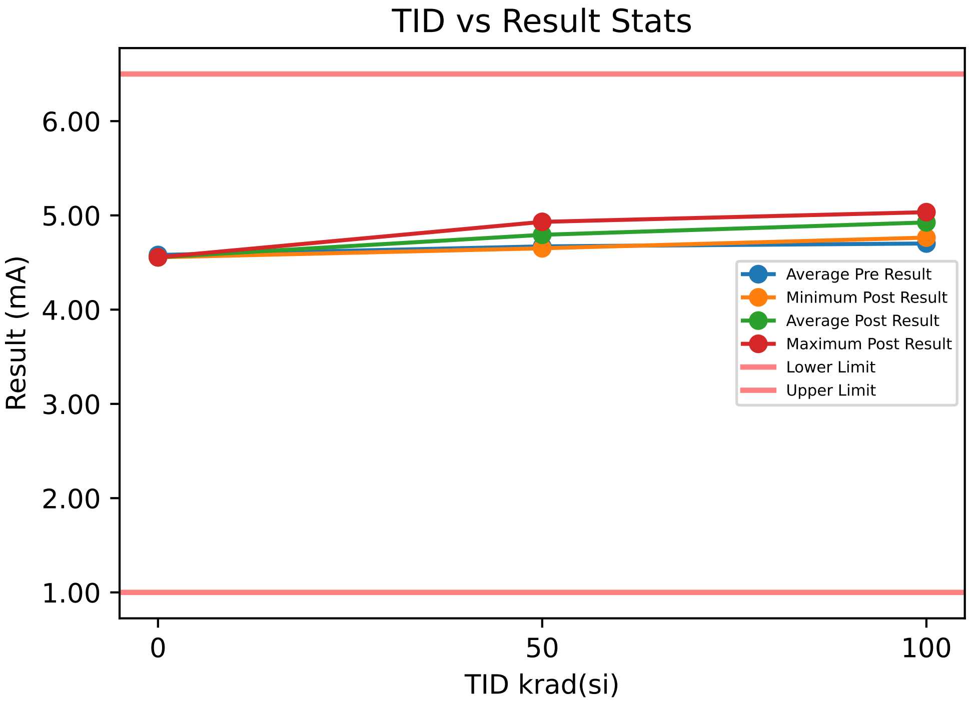
Test Results (Lower Limit = 1.0, Upper Limit = 9.0 (mA))

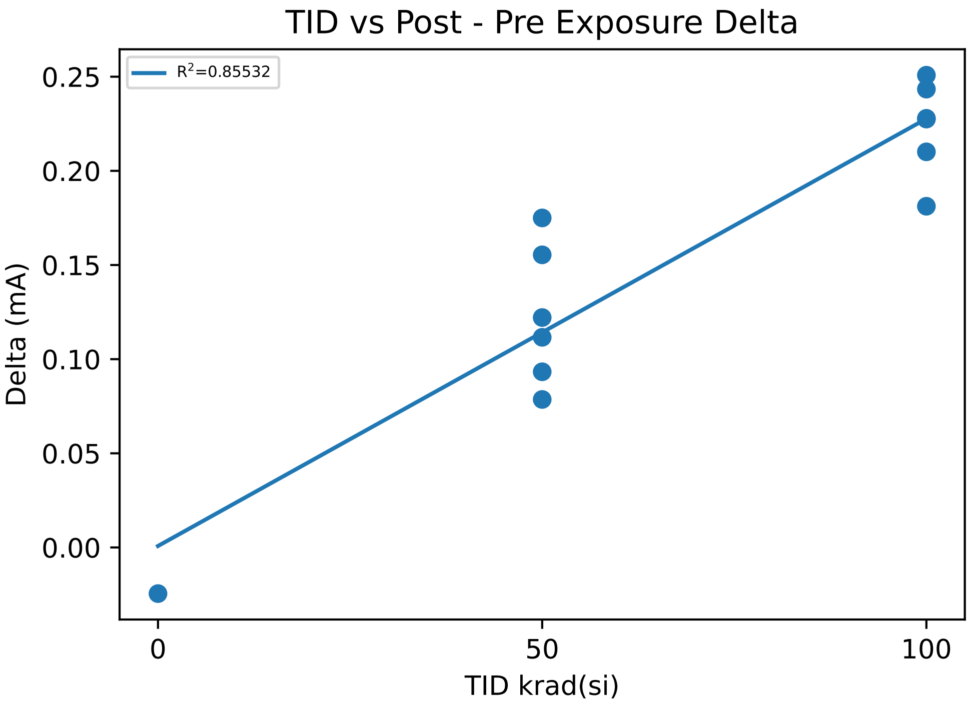
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.9586	6.0627	0.1041
60	50	Biased	5.9282	6.1078	0.1796
61	50	Biased	6.0204	6.1207	0.1003
63	100	Biased	6.0422	6.3225	0.2803
64	100	Biased	5.9368	6.2087	0.2719
65	100	Biased	5.97	6.2162	0.2462
66	50	Unbiased	6.0249	6.1559	0.131
67	50	Unbiased	5.9423	6.0128	0.0705
68	50	Unbiased	6.0965	6.3041	0.2076
69	100	Unbiased	6.1004	6.3693	0.2689
70	100	Unbiased	6.0837	6.4018	0.3181
71	100	Unbiased	5.9888	6.1696	0.1808
72	0	Control	5.8243	5.8454	0.0211

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8243	5.8243	5.8243		5.8454	5.8454	5.8454		0.0211	0.0211	0.0211	
50	5.9282	5.9951	6.0965	0.063884	6.0128	6.1273	6.3041	0.099783	0.0705	0.13218	0.2076	0.052053
100	5.9368	6.0203	6.1004	0.065437	6.1696	6.2813	6.4018	0.095862	0.1808	0.26103	0.3181	0.04575

Device Test: 36.15 Iop HS BOOT IIM Interlock 500kHz VIN_12V





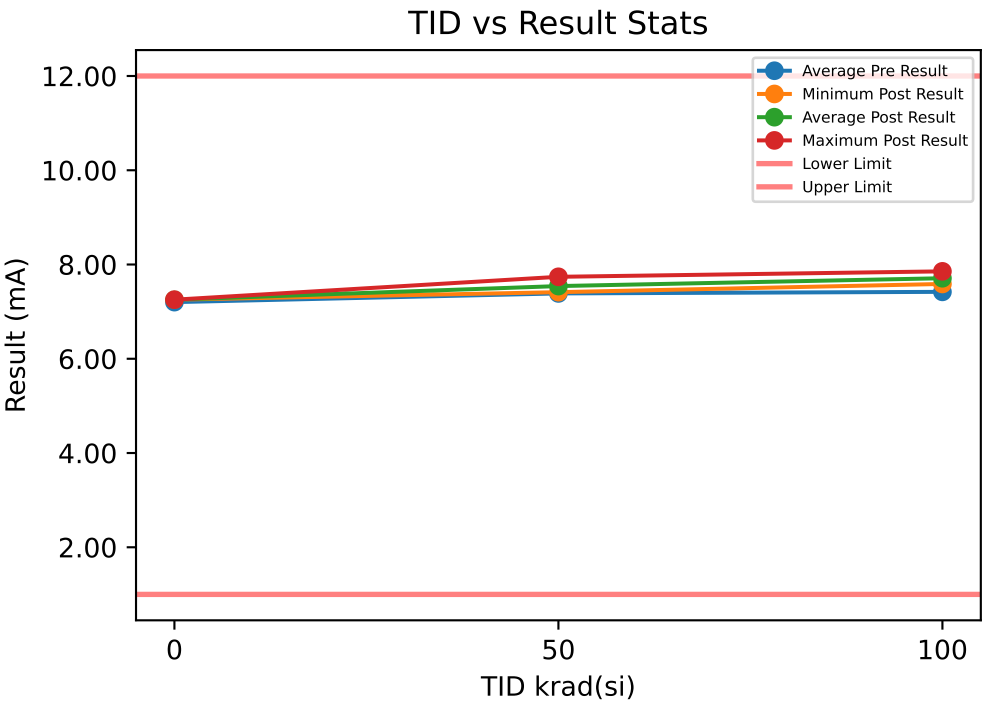
Test Results (Lower Limit = 1.0, Upper Limit = 6.5 (mA))

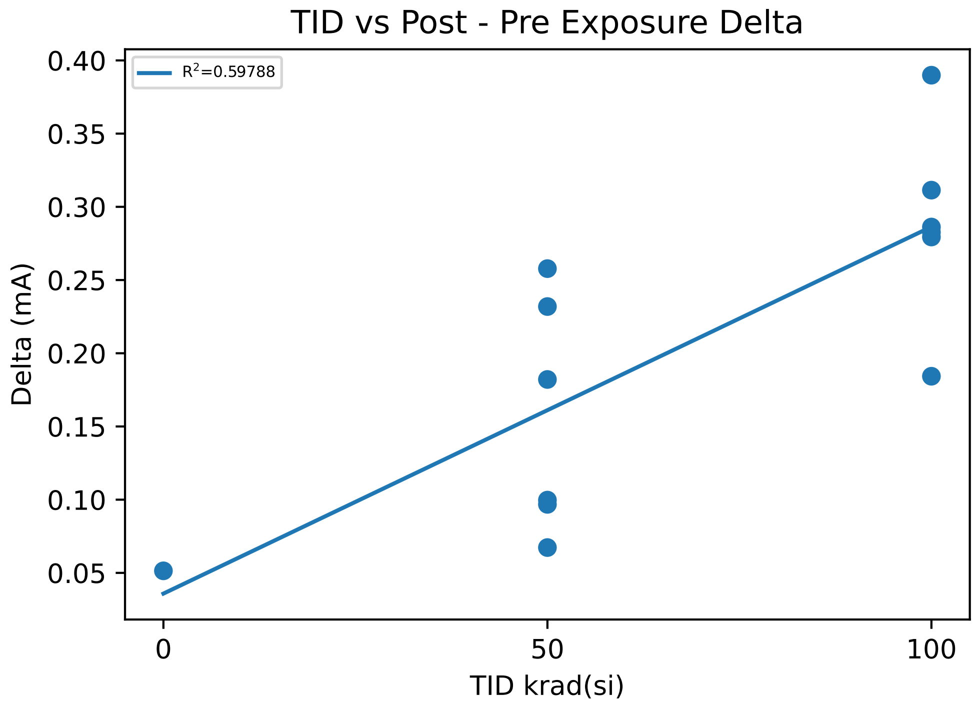
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.5391	4.6507	0.1116
60	50	Biased	4.6645	4.7866	0.1221
61	50	Biased	4.5291	4.7041	0.175
63	100	Biased	4.6849	4.9357	0.2508
64	100	Biased	4.5831	4.7643	0.1812
65	100	Biased	4.8061	5.034	0.2279
66	50	Unbiased	4.8479	4.9265	0.0786
67	50	Unbiased	4.7758	4.9312	0.1554
68	50	Unbiased	4.6708	4.7641	0.0933
69	100	Unbiased	4.6657	4.8758	0.2101
70	100	Unbiased	4.7205	4.948	0.2275
71	100	Unbiased	4.75	4.9934	0.2434
72	0	Control	4.5798	4.5553	-0.0245

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5798	4.5798	4.5798		4.5553	4.5553	4.5553		-0.0245	-0.0245	-0.0245	
50	4.5291	4.6712	4.8479	0.12637	4.6507	4.7939	4.9312	0.11484	0.0786	0.12267	0.175	0.036708
100	4.5831	4.7017	4.8061	0.076459	4.7643	4.9252	5.034	0.095339	0.1812	0.22348	0.2508	0.025082

Device Test: 36.16 Iop LS VIN IIM Interlock 1MHz VIN_12V





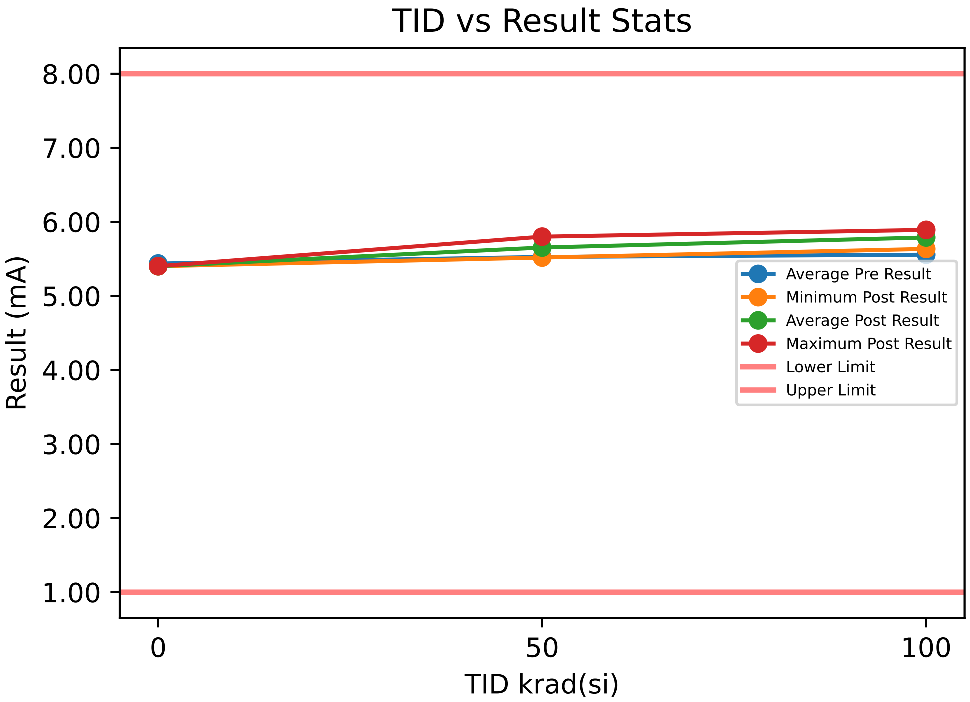
Test Results (Lower Limit = 1.0, Upper Limit = 12.0 (mA))

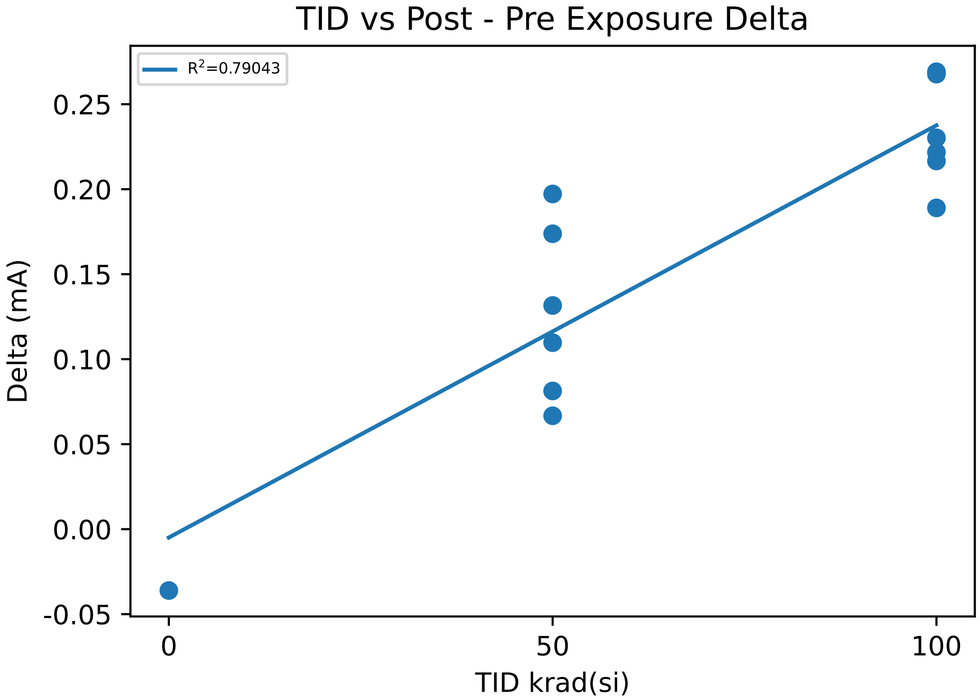
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.3634	7.4631	0.0997
60	50	Biased	7.3006	7.5325	0.2319
61	50	Biased	7.4232	7.52	0.0968
63	100	Biased	7.445	7.7312	0.2862
64	100	Biased	7.3123	7.6237	0.3114
65	100	Biased	7.3773	7.6567	0.2794
66	50	Unbiased	7.4041	7.5862	0.1821
67	50	Unbiased	7.3459	7.4132	0.0673
68	50	Unbiased	7.4812	7.739	0.2578
69	100	Unbiased	7.516	7.7986	0.2826
70	100	Unbiased	7.4649	7.8548	0.3899
71	100	Unbiased	7.4032	7.5875	0.1843
72	0	Control	7.202	7.2534	0.0514

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.202	7.202	7.202		7.2534	7.2534	7.2534		0.0514	0.0514	0.0514	
50	7.3006	7.3864	7.4812	0.063538	7.4132	7.5423	7.739	0.11327	0.0673	0.15593	0.2578	0.07918
100	7.3123	7.4198	7.516	0.0715	7.5875	7.7087	7.8548	0.10445	0.1843	0.28897	0.3899	0.066009

Device Test: 36.17 Iop HS BOOT IIM Interlock 1MHz VIN_12V





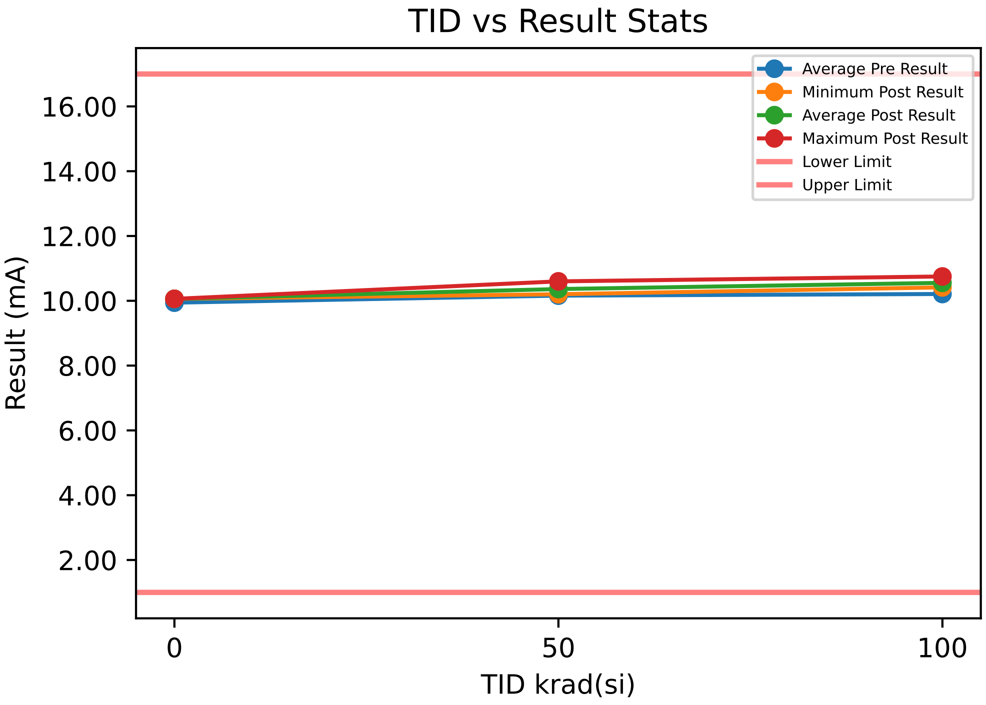
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

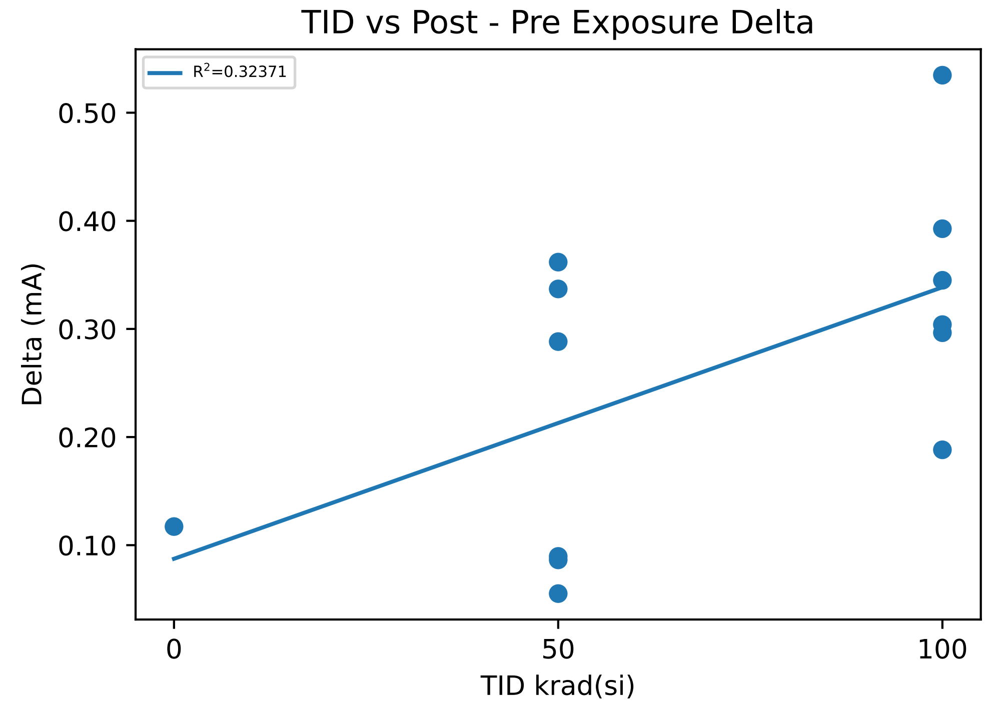
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.3866	5.5182	0.1316
60	50	Biased	5.5232	5.6329	0.1097
61	50	Biased	5.3776	5.5748	0.1972
63	100	Biased	5.5353	5.8044	0.2691
64	100	Biased	5.4459	5.6349	0.189
65	100	Biased	5.6618	5.892	0.2302
66	50	Unbiased	5.7093	5.776	0.0667
67	50	Unbiased	5.6268	5.8006	0.1738
68	50	Unbiased	5.5361	5.6174	0.0813
69	100	Unbiased	5.5198	5.7415	0.2217
70	100	Unbiased	5.5795	5.7961	0.2166
71	100	Unbiased	5.6003	5.868	0.2677
72	0	Control	5.4376	5.4015	-0.0361

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4376	5.4376	5.4376		5.4015	5.4015	5.4015		-0.0361	-0.0361	-0.0361	
50	5.3776	5.5266	5.7093	0.13063	5.5182	5.6533	5.8006	0.11214	0.0667	0.12672	0.1972	0.051309
100	5.4459	5.5571	5.6618	0.074246	5.6349	5.7895	5.892	0.092886	0.189	0.23238	0.2691	0.03113

Device Test: 36.18 Iop LS VIN IIM Interlock 2MHz VIN_12V





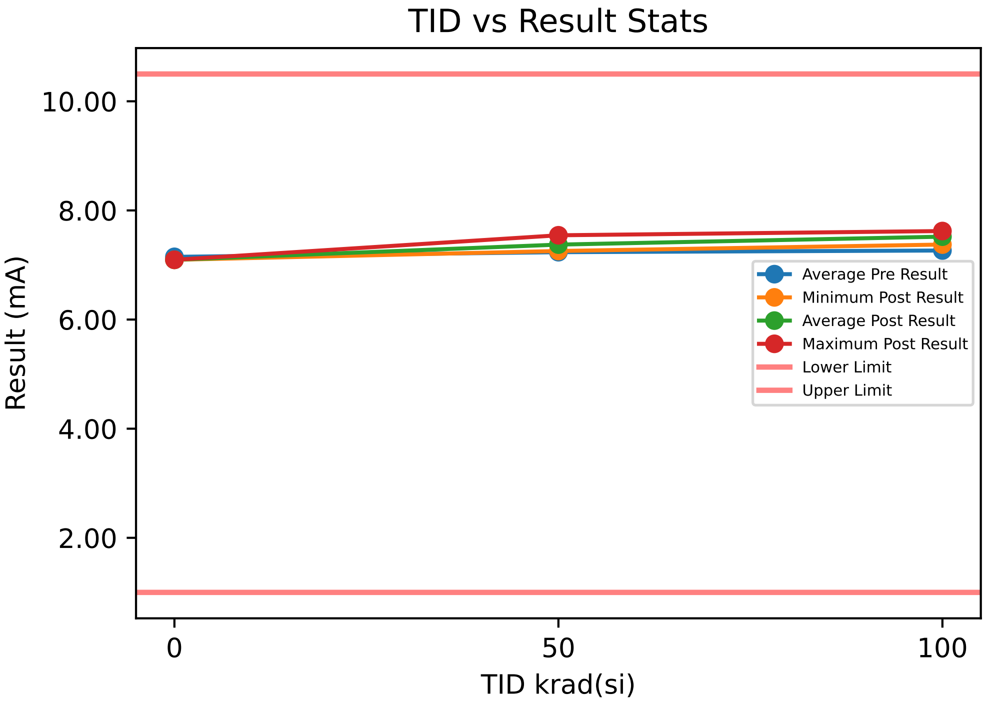
Test Results (Lower Limit = 1.0, Upper Limit = 17.0 (mA))

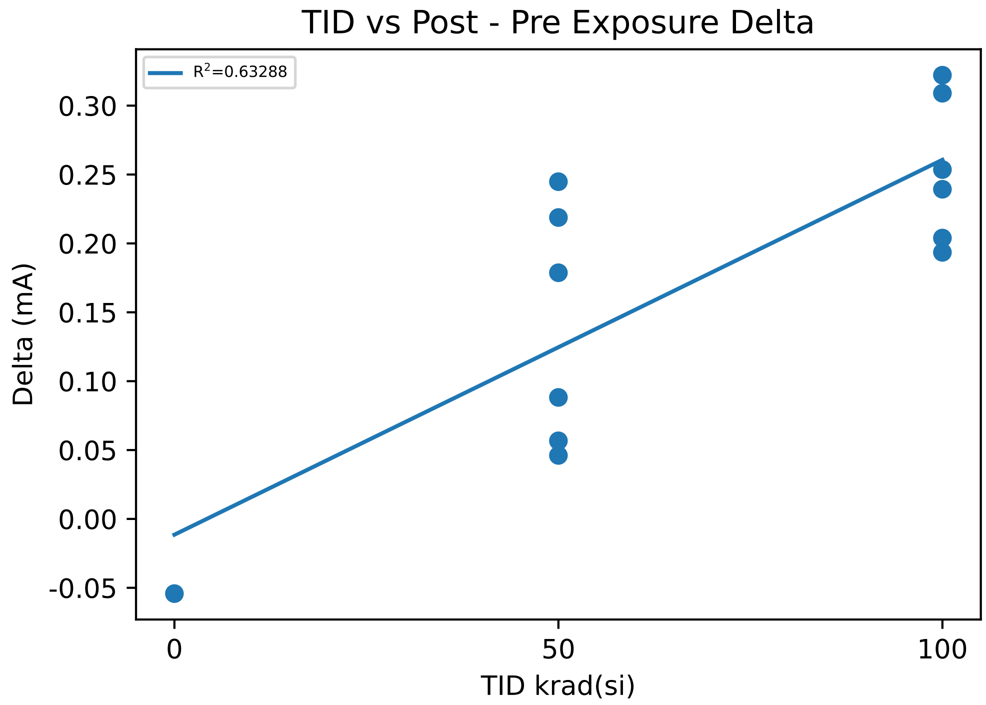
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	10.167	10.257	0.0896
60	50	Biased	10.034	10.371	0.337
61	50	Biased	10.221	10.308	0.0864
63	100	Biased	10.243	10.54	0.2965
64	100	Biased	10.05	10.442	0.3927
65	100	Biased	10.184	10.529	0.345
66	50	Unbiased	10.15	10.439	0.2883
67	50	Unbiased	10.147	10.202	0.0552
68	50	Unbiased	10.238	10.6	0.3618
69	100	Unbiased	10.341	10.645	0.304
70	100	Unbiased	10.216	10.751	0.5347
71	100	Unbiased	10.226	10.415	0.1882
72	0	Control	9.9427	10.06	0.1172

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.9427	9.9427	9.9427		10.06	10.06	10.06		0.1172	0.1172	0.1172	
50	10.034	10.16	10.238	0.072245	10.202	10.363	10.6	0.1429	0.0552	0.20305	0.3618	0.14053
100	10.05	10.21	10.341	0.094912	10.415	10.554	10.751	0.12626	0.1882	0.34352	0.5347	0.11564

Device Test: 36.19 Iop HS BOOT IIM Interlock 2MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

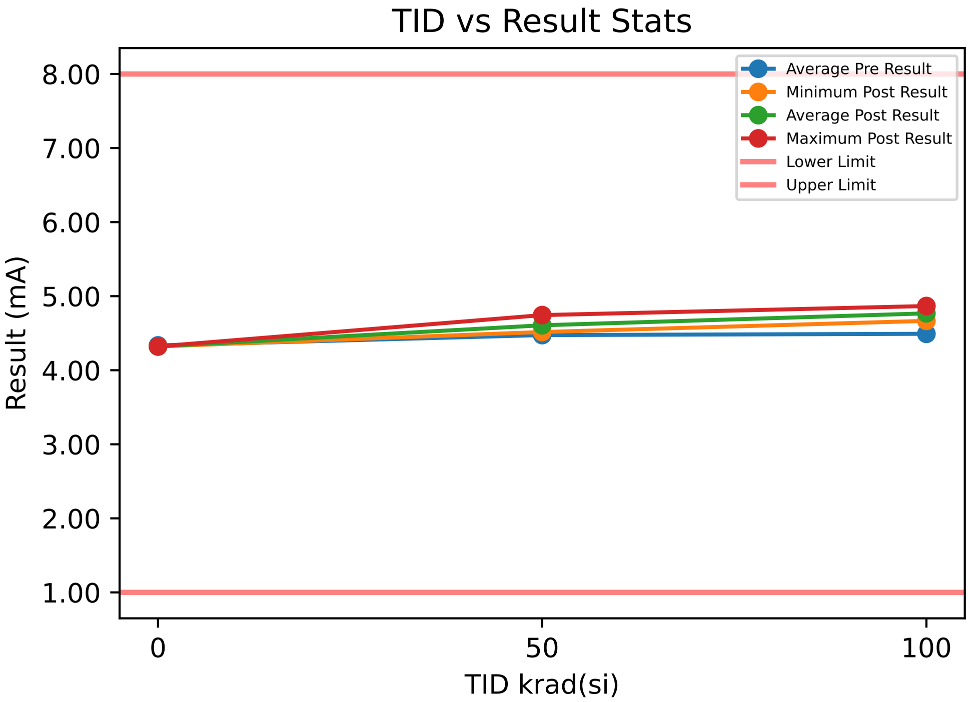
Test Results (Lower Limit = 1.0, Upper Limit = 10.5 (mA))

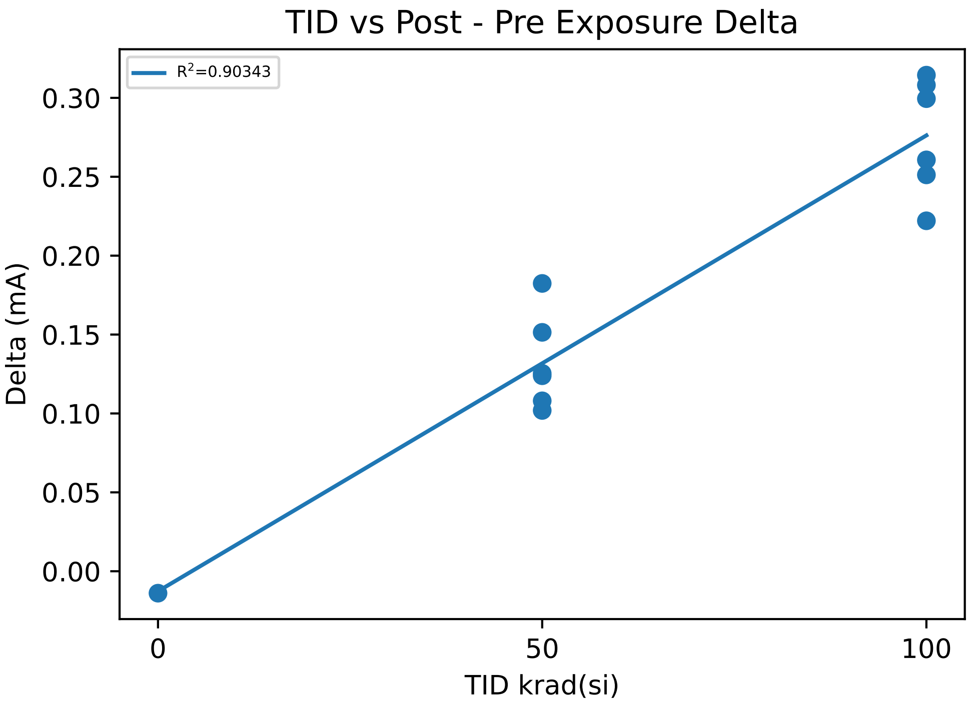
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0778	7.2565	0.1787
60	50	Biased	7.2394	7.3276	0.0882
61	50	Biased	7.0723	7.3171	0.2448
63	100	Biased	7.2376	7.5466	0.309
64	100	Biased	7.1705	7.3744	0.2039
65	100	Biased	7.3712	7.6105	0.2393
66	50	Unbiased	7.4271	7.4732	0.0461
67	50	Unbiased	7.3256	7.5444	0.2188
68	50	Unbiased	7.2652	7.3219	0.0567
69	100	Unbiased	7.2188	7.4724	0.2536
70	100	Unbiased	7.294	7.4875	0.1935
71	100	Unbiased	7.3	7.6221	0.3221
72	0	Control	7.1492	7.095	-0.0542

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1492	7.1492	7.1492		7.095	7.095	7.095		-0.0542	-0.0542	-0.0542	
50	7.0723	7.2346	7.4271	0.13944	7.2565	7.3735	7.5444	0.11026	0.0461	0.13888	0.2448	0.086165
100	7.1705	7.2654	7.3712	0.070935	7.3744	7.5189	7.6221	0.093634	0.1935	0.25357	0.3221	0.053006

Device Test: 36.2 Iq LS VIN IIM Interlock VIN_12V





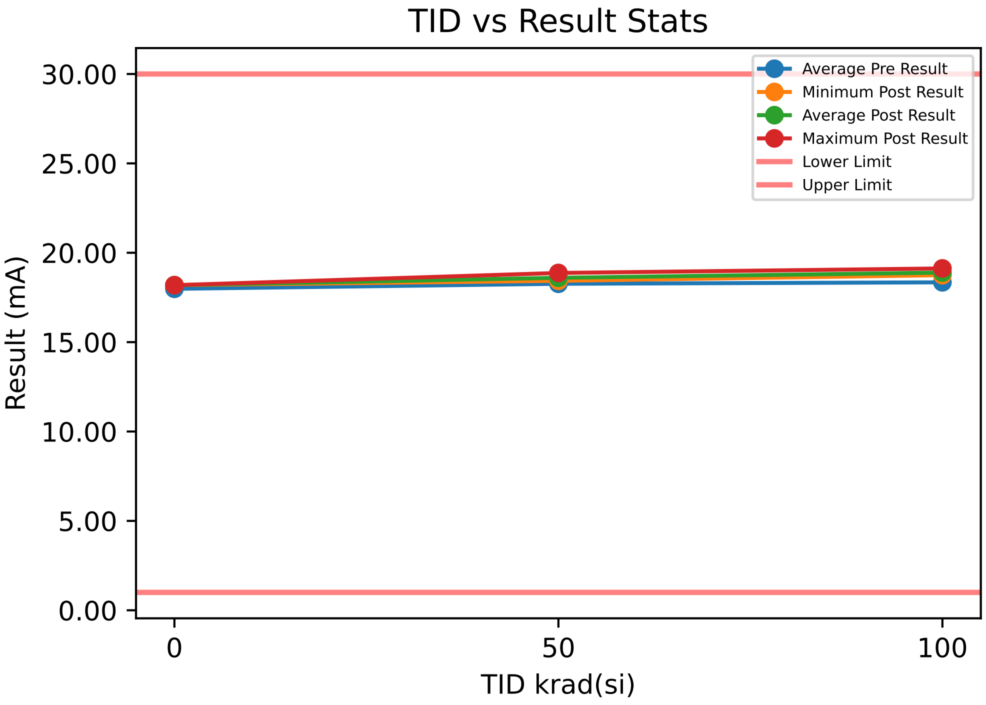
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

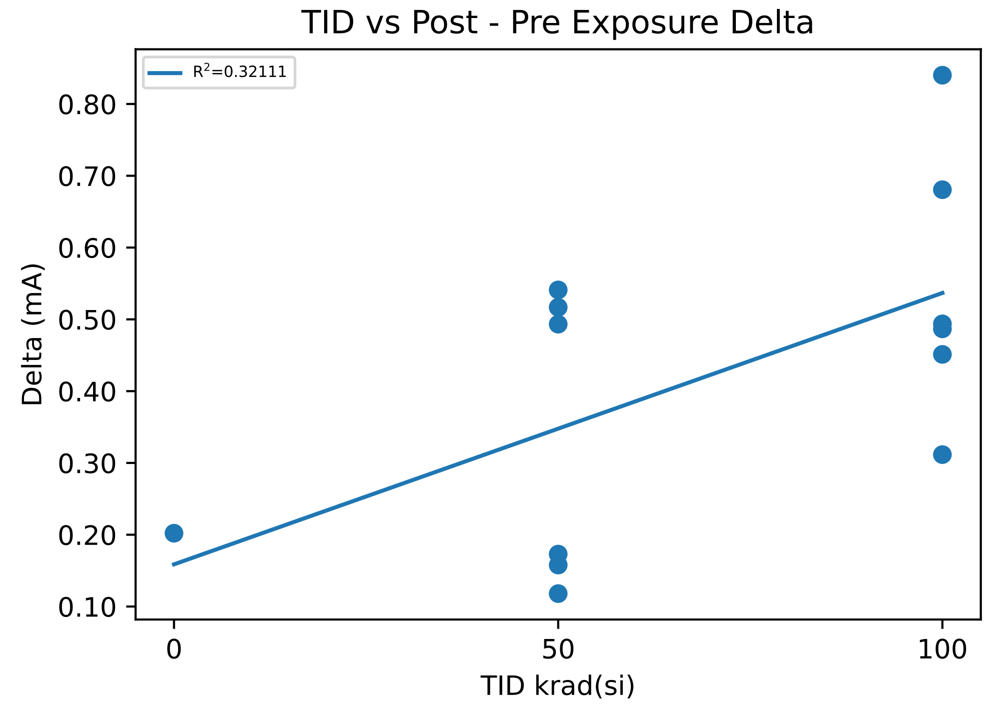
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.4453	4.5707	0.1254
60	50	Biased	4.4464	4.5978	0.1514
61	50	Biased	4.4956	4.6195	0.1239
63	100	Biased	4.4964	4.8108	0.3144
64	100	Biased	4.4506	4.7113	0.2607
65	100	Biased	4.4358	4.687	0.2512
66	50	Unbiased	4.4838	4.5918	0.108
67	50	Unbiased	4.4142	4.5161	0.1019
68	50	Unbiased	4.5619	4.7443	0.1824
69	100	Unbiased	4.5586	4.8667	0.3081
70	100	Unbiased	4.5654	4.8649	0.2995
71	100	Unbiased	4.4446	4.6667	0.2221
72	0	Control	4.3351	4.3212	-0.0139

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3351	4.3351	4.3351		4.3212	4.3212	4.3212		-0.0139	-0.0139	-0.0139	
50	4.4142	4.4745	4.5619	0.051863	4.5161	4.6067	4.7443	0.07603	0.1019	0.13217	0.1824	0.030025
100	4.4358	4.4919	4.5654	0.058244	4.6667	4.7679	4.8667	0.090555	0.2221	0.276	0.3144	0.03691

Device Test: 36.20 Iop LS VIN IIM Interlock 5MHz VIN_12V





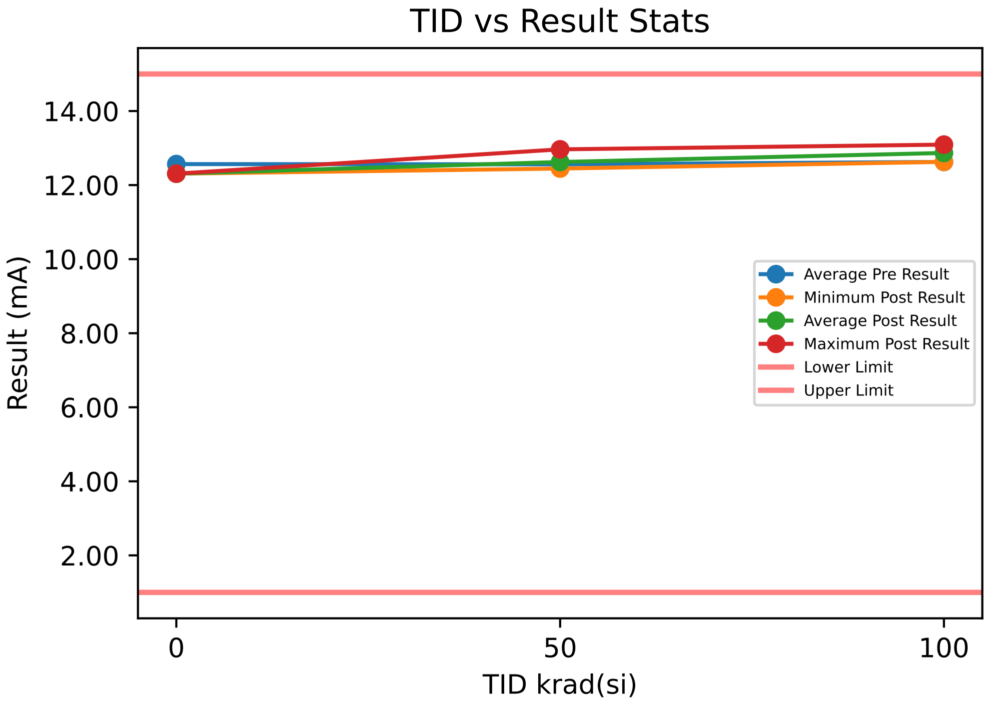
Test Results (Lower Limit = 1.0, Upper Limit = 30.0 (mA))

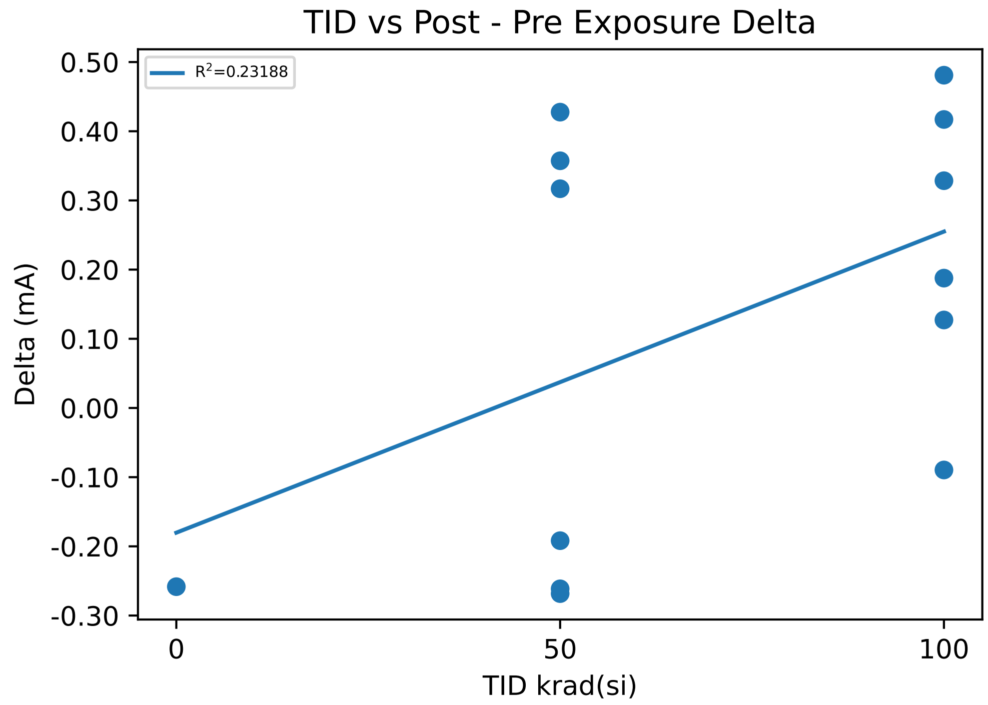
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	18.328	18.501	0.173
60	50	Biased	18.056	18.572	0.5168
61	50	Biased	18.367	18.524	0.1578
63	100	Biased	18.378	18.829	0.4512
64	100	Biased	18.079	18.76	0.6806
65	100	Biased	18.353	18.84	0.4868
66	50	Unbiased	18.2	18.693	0.4933
67	50	Unbiased	18.313	18.431	0.118
68	50	Unbiased	18.329	18.87	0.541
69	100	Unbiased	18.548	19.042	0.4937
70	100	Unbiased	18.283	19.123	0.8401
71	100	Unbiased	18.435	18.747	0.3116
72	0	Control	17.984	18.186	0.2021

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.984	17.984	17.984		18.186	18.186	18.186		0.2021	0.2021	0.2021	
50	18.056	18.265	18.367	0.11728	18.431	18.599	18.87	0.15889	0.118	0.33332	0.541	0.20261
100	18.079	18.346	18.548	0.15815	18.747	18.89	19.123	0.15561	0.3116	0.544	0.8401	0.18695

Device Test: 36.21 Iop HS BOOT IIM Interlock 5MHz VIN_12V





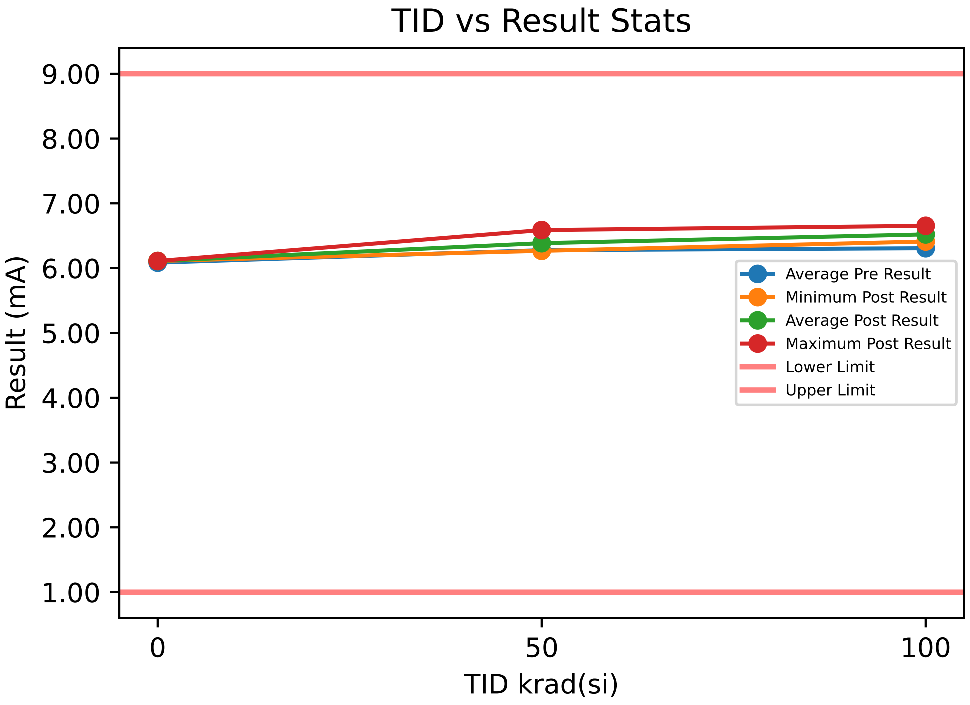
Test Results (Lower Limit = 1.0, Upper Limit = 15.0 (mA))

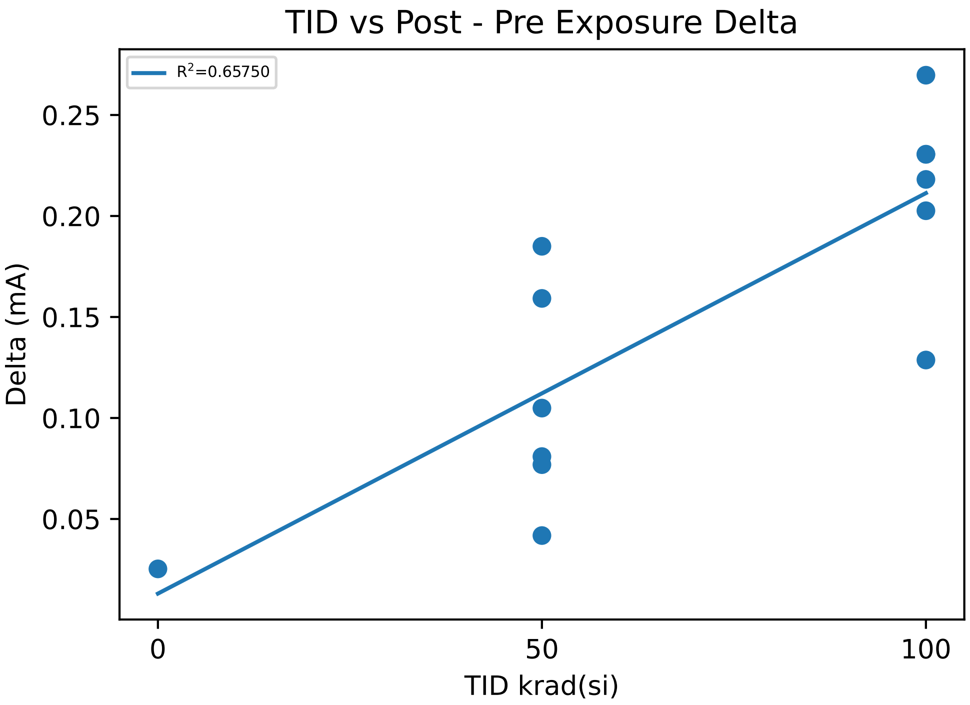
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	12.314	12.631	0.3169
60	50	Biased	12.644	12.452	-0.1918
61	50	Biased	12.255	12.682	0.4276
63	100	Biased	12.553	12.97	0.417
64	100	Biased	12.616	12.804	0.1877
65	100	Biased	12.748	12.875	0.1272
66	50	Unbiased	12.832	12.564	-0.2683
67	50	Unbiased	12.608	12.965	0.3573
68	50	Unbiased	12.708	12.447	-0.2614
69	100	Unbiased	12.509	12.838	0.3285
70	100	Unbiased	12.717	12.627	-0.0896
71	100	Unbiased	12.611	13.092	0.481
72	0	Control	12.567	12.309	-0.2583

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.567	12.567	12.567		12.309	12.309	12.309		-0.2583	-0.2583	-0.2583	
50	12.255	12.56	12.832	0.22748	12.447	12.624	12.965	0.19211	-0.2683	0.063383	0.4276	0.33584
100	12.509	12.626	12.748	0.092064	12.627	12.868	13.092	0.1573	-0.0896	0.24197	0.481	0.21039

Device Test: 36.22 Iop LS VIN IIM Interlock Disable 500kHz VIN_12V





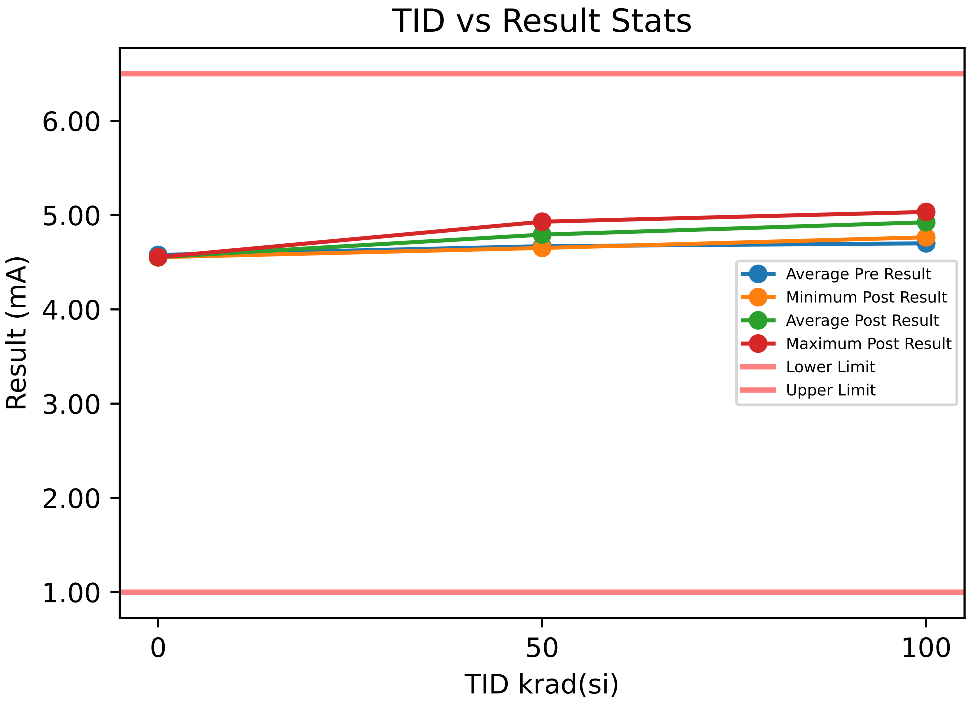
Test Results (Lower Limit = 1.0, Upper Limit = 9.0 (mA))

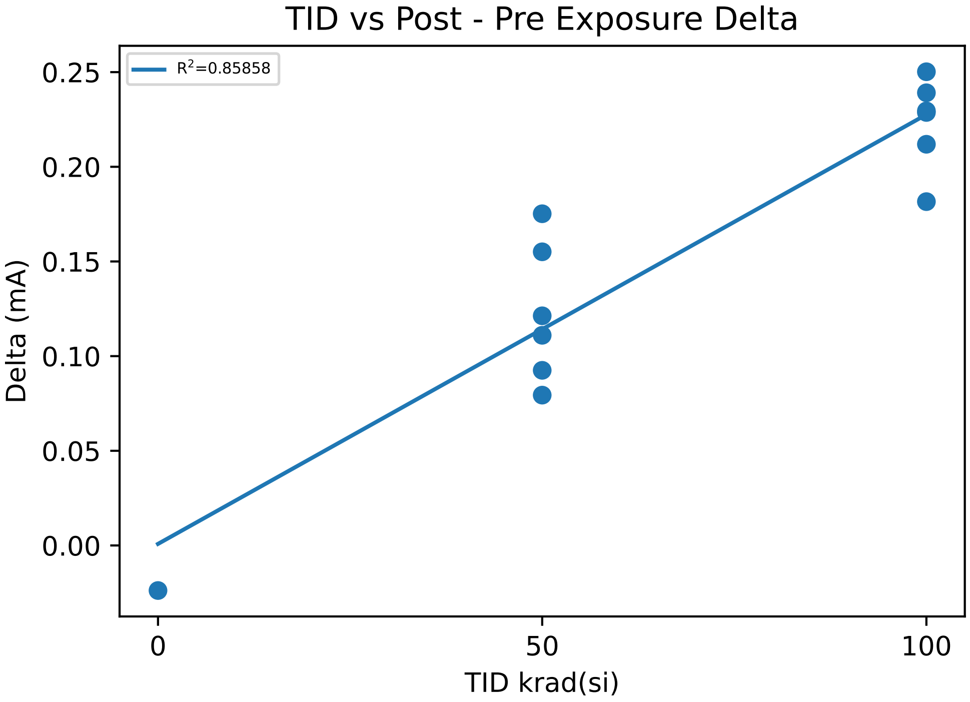
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.2163	6.2972	0.0809
60	50	Biased	6.1821	6.3413	0.1592
61	50	Biased	6.2914	6.3683	0.0769
63	100	Biased	6.3405	6.571	0.2305
64	100	Biased	6.1957	6.4263	0.2306
65	100	Biased	6.2544	6.457	0.2026
66	50	Unbiased	6.347	6.4519	0.1049
67	50	Unbiased	6.2254	6.2672	0.0418
68	50	Unbiased	6.4024	6.5874	0.185
69	100	Unbiased	6.3877	6.6058	0.2181
70	100	Unbiased	6.3838	6.6535	0.2697
71	100	Unbiased	6.2826	6.4113	0.1287
72	0	Control	6.085	6.1103	0.0253

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.085	6.085	6.085		6.1103	6.1103	6.1103		0.0253	0.0253	0.0253	
50	6.1821	6.2774	6.4024	0.08507	6.2672	6.3855	6.5874	0.11766	0.0418	0.10812	0.185	0.054118
100	6.1957	6.3075	6.3877	0.076527	6.4113	6.5208	6.6535	0.10232	0.1287	0.21337	0.2697	0.047055

Device Test: 36.23 Iop HS BOOT IIM Interlock Disable 500kHz VIN_12V





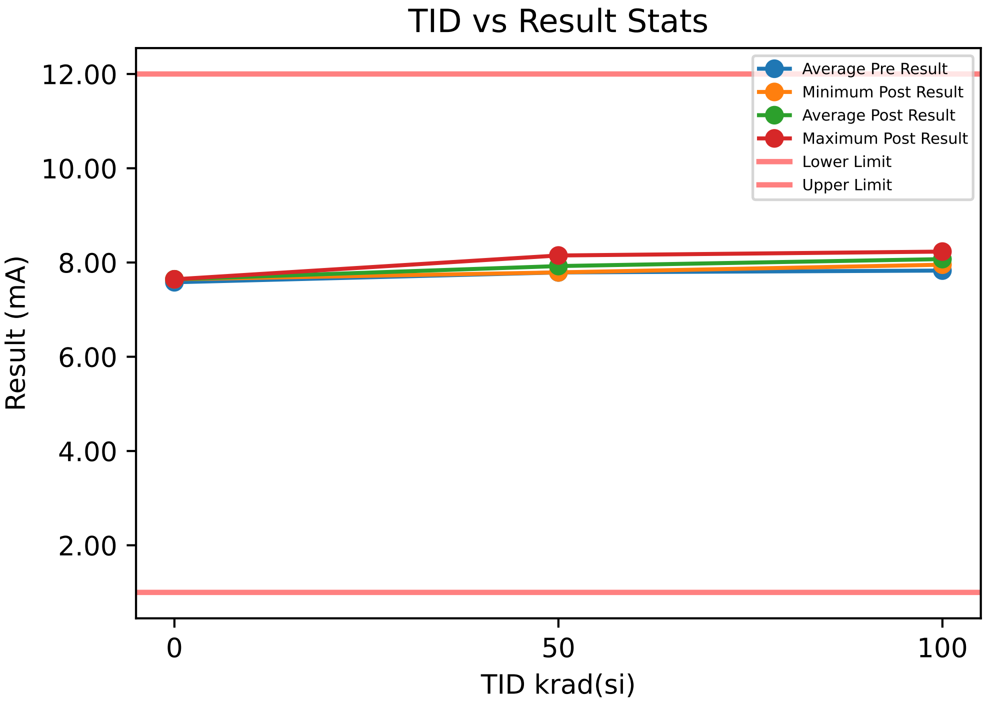
Test Results (Lower Limit = 1.0, Upper Limit = 6.5 (mA))

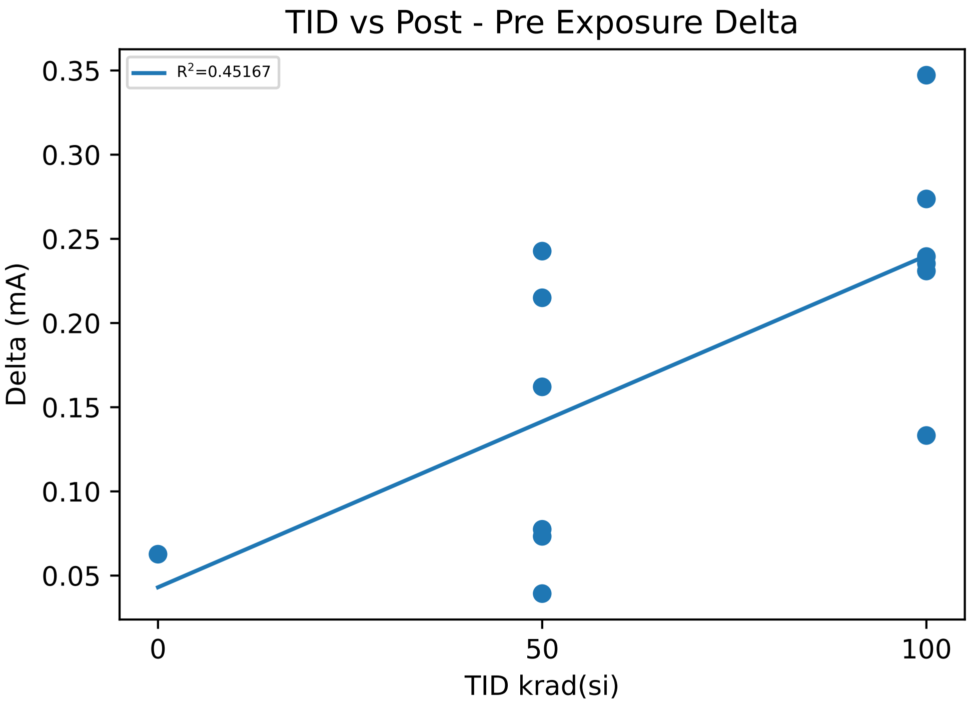
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.5406	4.6516	0.111
60	50	Biased	4.6641	4.7854	0.1213
61	50	Biased	4.5281	4.7033	0.1752
63	100	Biased	4.6838	4.934	0.2502
64	100	Biased	4.5832	4.7648	0.1816
65	100	Biased	4.8043	5.0338	0.2295
66	50	Unbiased	4.846	4.9254	0.0794
67	50	Unbiased	4.7749	4.93	0.1551
68	50	Unbiased	4.6693	4.7618	0.0925
69	100	Unbiased	4.6651	4.877	0.2119
70	100	Unbiased	4.7183	4.947	0.2287
71	100	Unbiased	4.75	4.9891	0.2391
72	0	Control	4.5776	4.5538	-0.0238

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5776	4.5776	4.5776		4.5538	4.5538	4.5538		-0.0238	-0.0238	-0.0238	
50	4.5281	4.6705	4.846	0.12561	4.6516	4.7929	4.93	0.11434	0.0794	0.12242	0.1752	0.036691
100	4.5832	4.7008	4.8043	0.075937	4.7648	4.9243	5.0338	0.094315	0.1816	0.2235	0.2502	0.024122

Device Test: 36.24 Iop LS VIN IIM Interlock Disable 1MHz VIN_12V





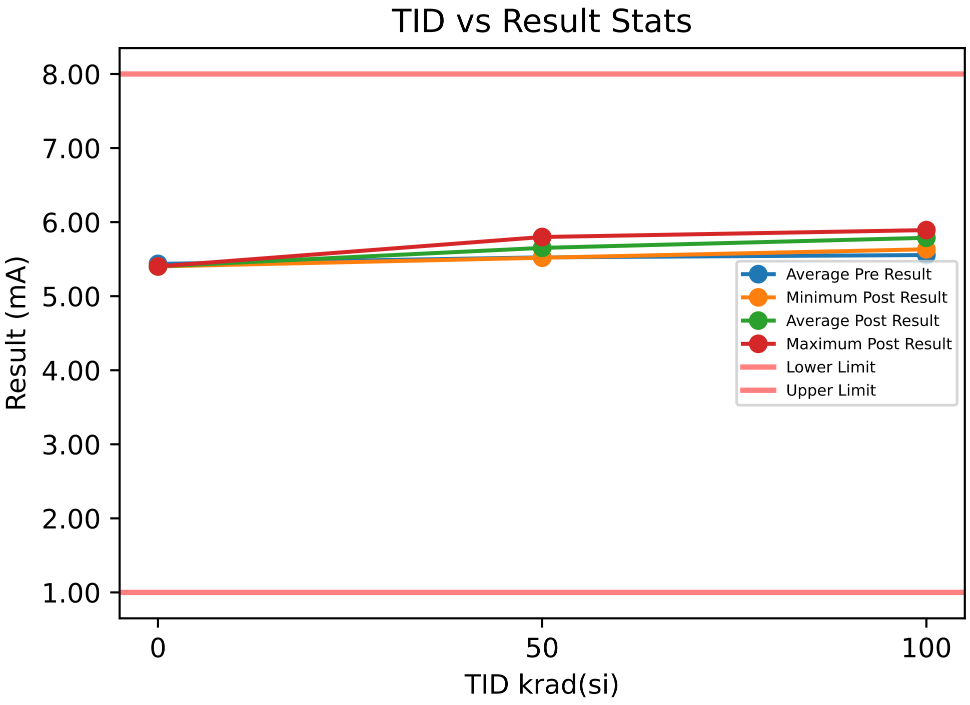
Test Results (Lower Limit = 1.0, Upper Limit = 12.0 (mA))

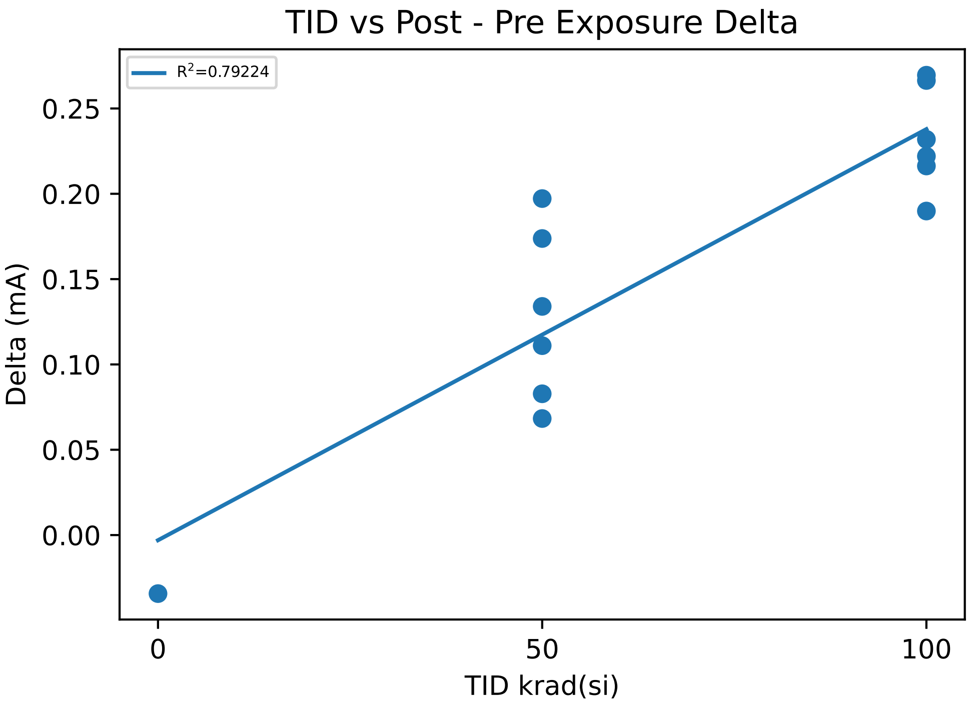
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.7435	7.821	0.0775
60	50	Biased	7.6746	7.8896	0.215
61	50	Biased	7.8151	7.8884	0.0733
63	100	Biased	7.8663	8.1016	0.2353
64	100	Biased	7.6899	7.9636	0.2737
65	100	Biased	7.7845	8.024	0.2395
66	50	Unbiased	7.8453	8.0074	0.1621
67	50	Unbiased	7.7513	7.7906	0.0393
68	50	Unbiased	7.9063	8.149	0.2427
69	100	Unbiased	7.9274	8.1583	0.2309
70	100	Unbiased	7.8845	8.2317	0.3472
71	100	Unbiased	7.8204	7.9536	0.1332
72	0	Control	7.5808	7.6435	0.0627

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.5808	7.5808	7.5808		7.6435	7.6435	7.6435		0.0627	0.0627	0.0627	
50	7.6746	7.7893	7.9063	0.08269	7.7906	7.9243	8.149	0.13299	0.0393	0.13498	0.2427	0.083672
100	7.6899	7.8288	7.9274	0.084329	7.9536	8.0721	8.2317	0.11127	0.1332	0.2433	0.3472	0.069388

Device Test: 36.25 Iop HS BOOT IIM Interlock Disable 1MHz VIN_12V





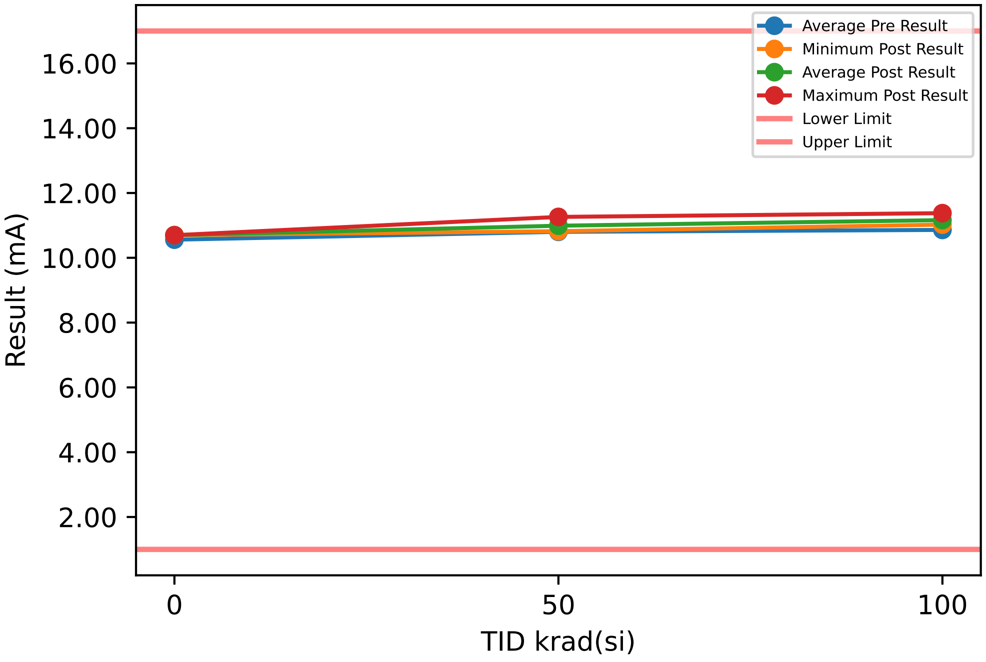
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

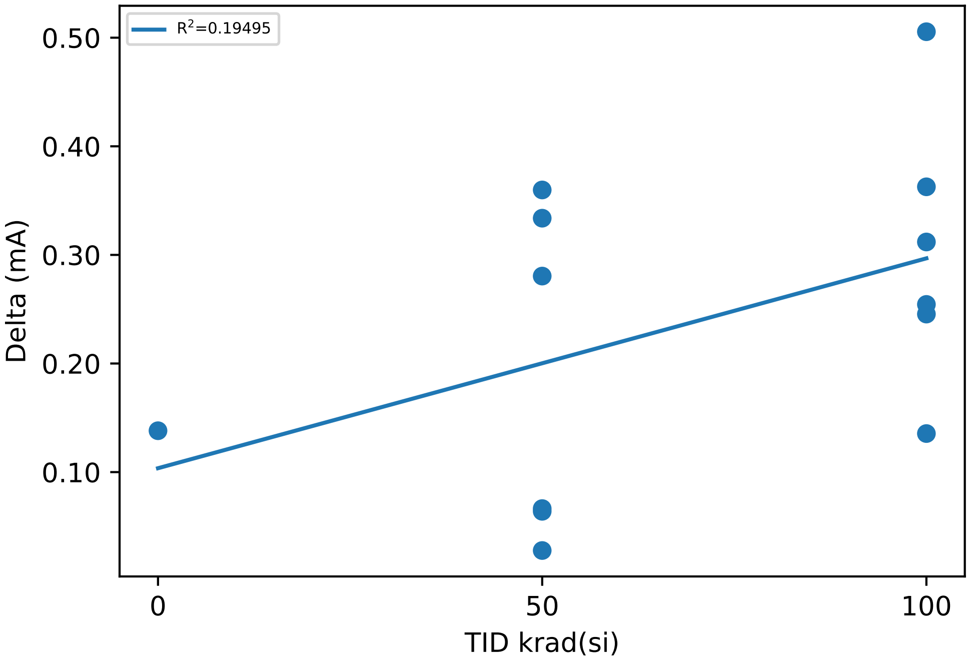
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.3848	5.5188	0.134
60	50	Biased	5.5207	5.6317	0.111
61	50	Biased	5.3754	5.5726	0.1972
63	100	Biased	5.5347	5.8042	0.2695
64	100	Biased	5.4432	5.6331	0.1899
65	100	Biased	5.6603	5.8922	0.2319
66	50	Unbiased	5.7062	5.7745	0.0683
67	50	Unbiased	5.6251	5.7989	0.1738
68	50	Unbiased	5.5323	5.6151	0.0828
69	100	Unbiased	5.5172	5.7392	0.222
70	100	Unbiased	5.5776	5.7939	0.2163
71	100	Unbiased	5.6	5.8664	0.2664
72	0	Control	5.4359	5.4016	-0.0343

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4359	5.4359	5.4359		5.4016	5.4016	5.4016		-0.0343	-0.0343	-0.0343	
50	5.3754	5.5241	5.7062	0.13035	5.5188	5.6519	5.7989	0.11172	0.0683	0.12785	0.1972	0.050633
100	5.4432	5.5555	5.6603	0.074783	5.6331	5.7882	5.8922	0.093463	0.1899	0.23267	0.2695	0.030679

Device Test: 36.26 Iop LS VIN IIM Interlock Disable 2MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

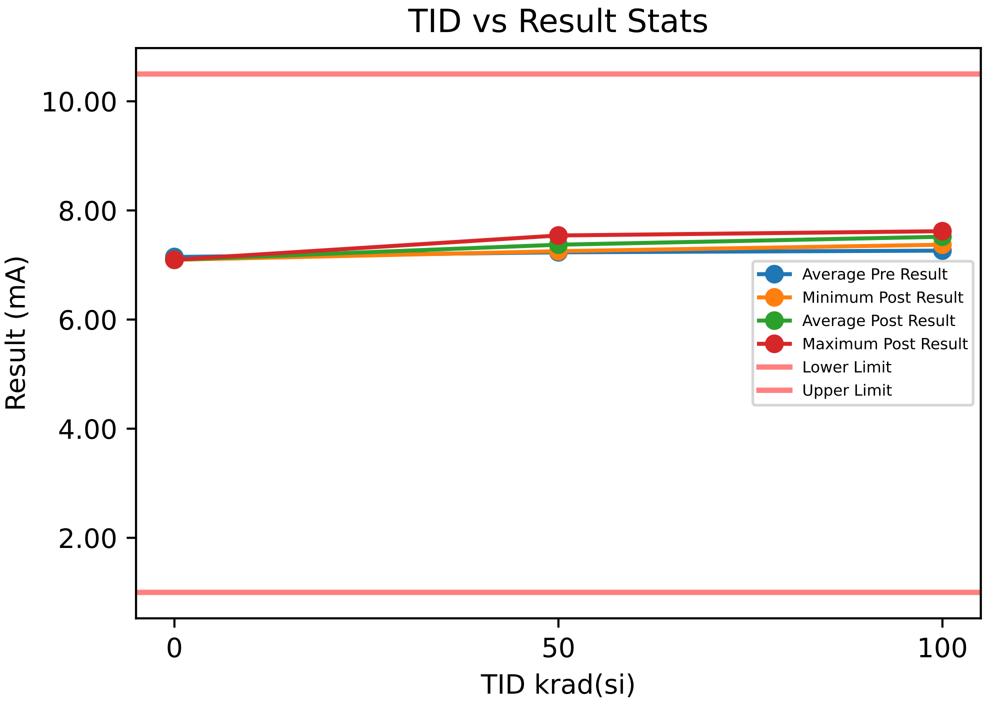
Test Results (Lower Limit = 1.0, Upper Limit = 17.0 (mA))

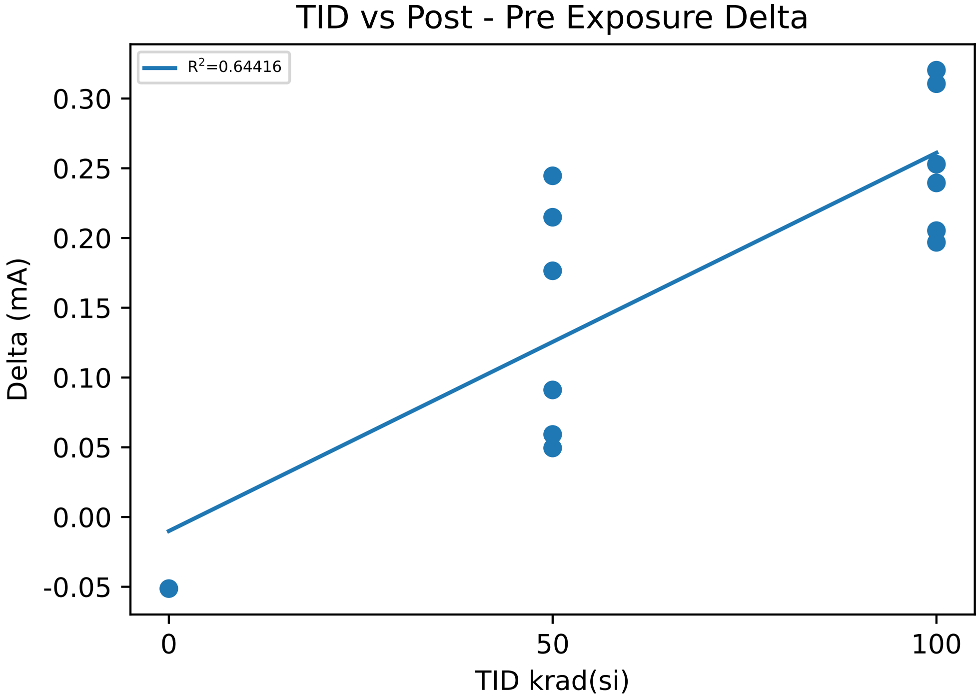
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	10.789	10.855	0.0664
60	50	Biased	10.643	10.977	0.3338
61	50	Biased	10.854	10.918	0.0639
63	100	Biased	10.907	11.153	0.2455
64	100	Biased	10.665	11.027	0.3627
65	100	Biased	10.836	11.148	0.3119
66	50	Unbiased	10.828	11.108	0.2805
67	50	Unbiased	10.793	10.821	0.0278
68	50	Unbiased	10.902	11.262	0.3598
69	100	Unbiased	10.996	11.25	0.2544
70	100	Unbiased	10.872	11.378	0.5055
71	100	Unbiased	10.888	11.024	0.1355
72	0	Control	10.559	10.698	0.1381

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.559	10.559	10.559		10.698	10.698	10.698		0.1381	0.1381	0.1381	
50	10.643	10.802	10.902	0.088116	10.821	10.99	11.262	0.16729	0.0278	0.1887	0.3598	0.15177
100	10.665	10.861	10.996	0.10995	11.024	11.163	11.378	0.1355	0.1355	0.30258	0.5055	0.1252

Device Test: 36.27 Iop HS BOOT IIM Interlock Disable 2MHz VIN_12V





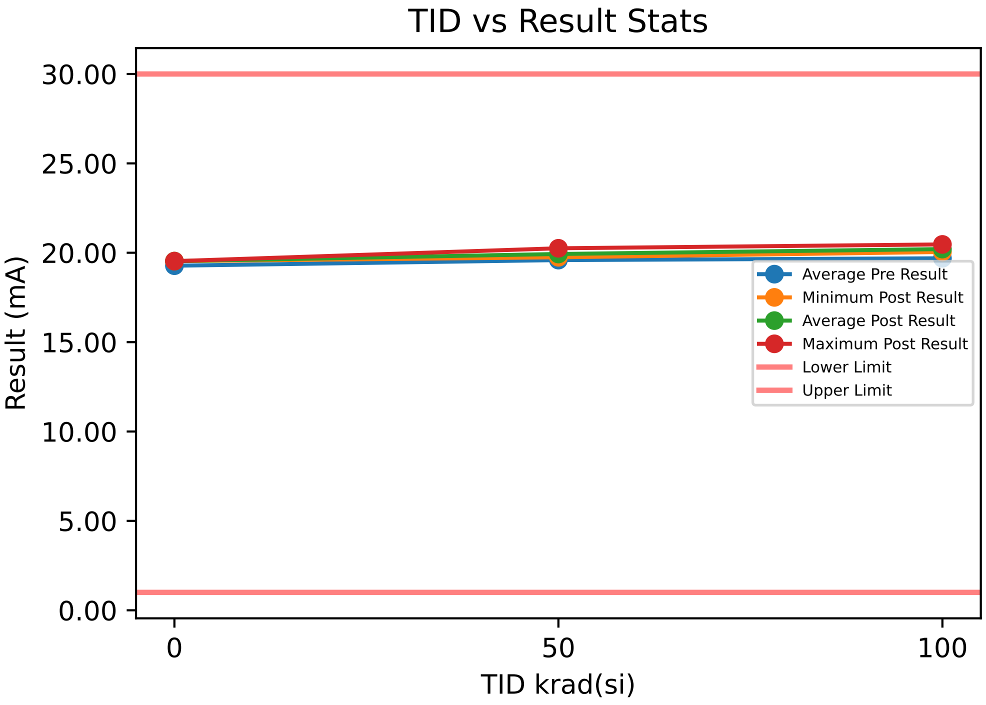
Test Results (Lower Limit = 1.0, Upper Limit = 10.5 (mA))

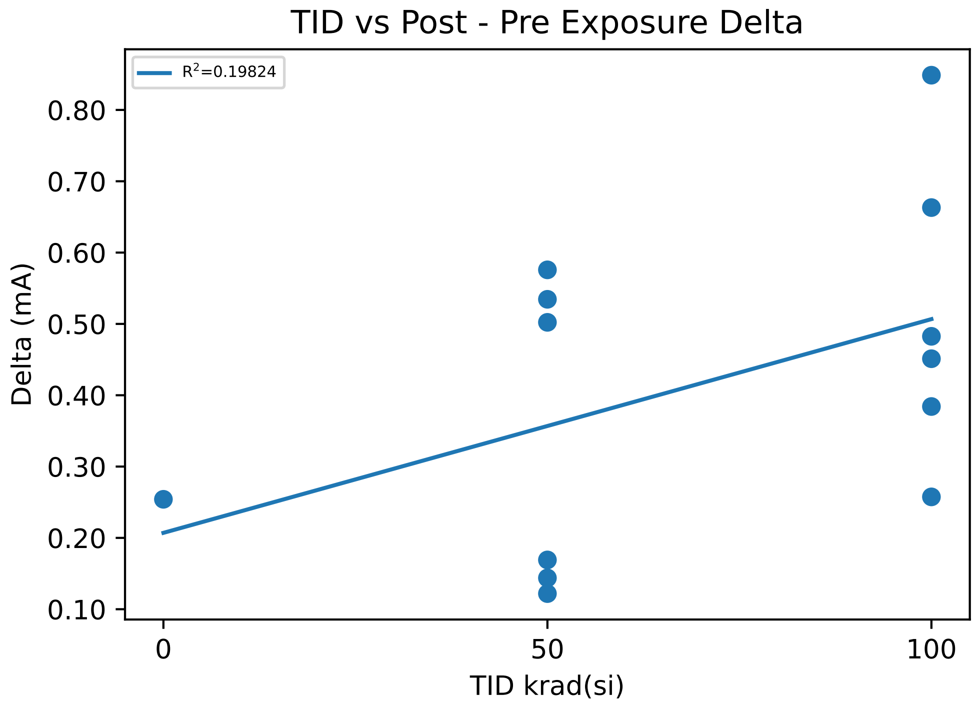
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0761	7.2526	0.1765
60	50	Biased	7.2353	7.3264	0.0911
61	50	Biased	7.0703	7.3149	0.2446
63	100	Biased	7.236	7.5466	0.3106
64	100	Biased	7.1665	7.3718	0.2053
65	100	Biased	7.37	7.6095	0.2395
66	50	Unbiased	7.4242	7.4737	0.0495
67	50	Unbiased	7.326	7.5409	0.2149
68	50	Unbiased	7.2617	7.3209	0.0592
69	100	Unbiased	7.2174	7.4703	0.2529
70	100	Unbiased	7.2905	7.4874	0.1969
71	100	Unbiased	7.299	7.6193	0.3203
72	0	Control	7.1468	7.0955	-0.0513

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1468	7.1468	7.1468		7.0955	7.0955	7.0955		-0.0513	-0.0513	-0.0513	
50	7.0703	7.2323	7.4242	0.13937	7.2526	7.3716	7.5409	0.11052	0.0495	0.1393	0.2446	0.083655
100	7.1665	7.2632	7.37	0.071584	7.3718	7.5175	7.6193	0.093847	0.1969	0.25425	0.3203	0.051851

Device Test: 36.28 Iop LS VIN IIM Interlock Disable 5MHz VIN_12V





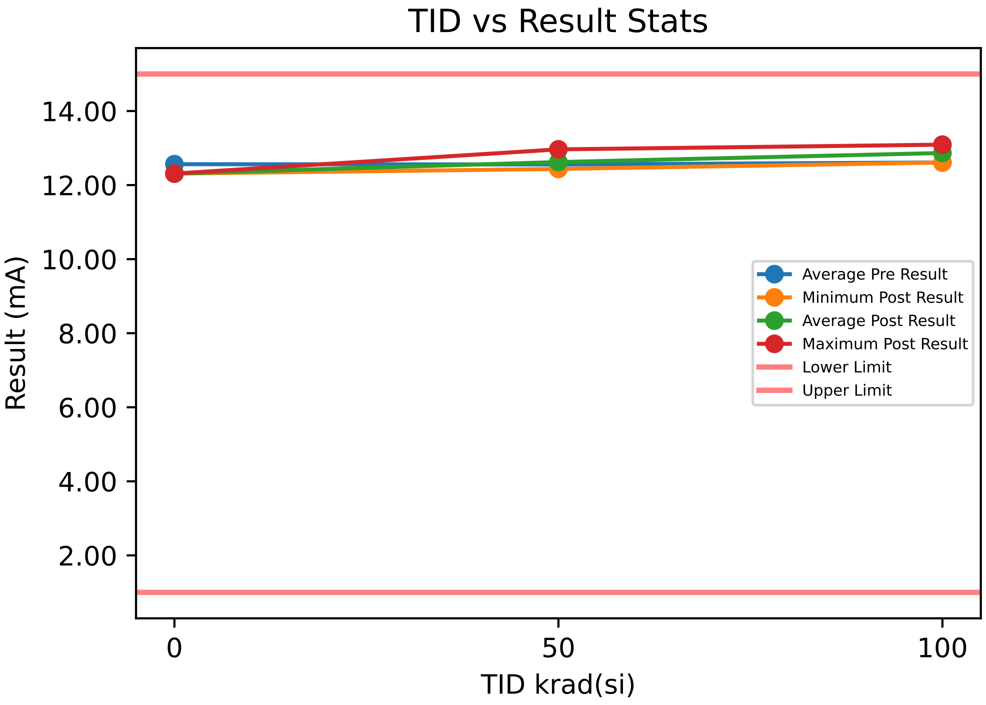
Test Results (Lower Limit = 1.0, Upper Limit = 30.0 (mA))

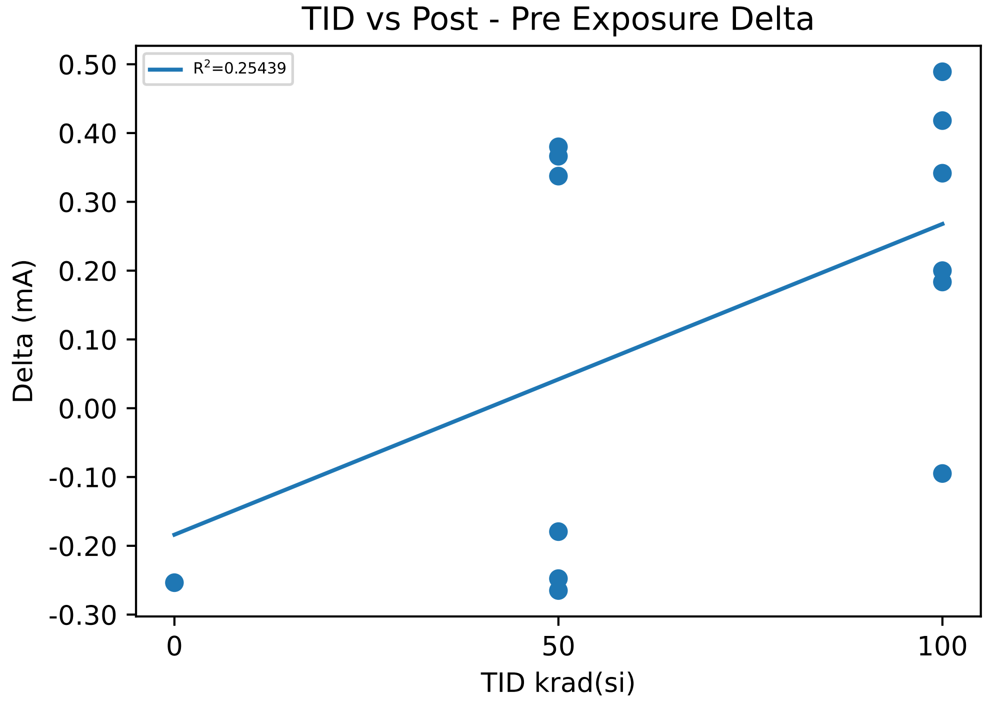
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	19.629	19.798	0.1691
60	50	Biased	19.349	19.884	0.5345
61	50	Biased	19.691	19.835	0.1438
63	100	Biased	19.754	20.138	0.3842
64	100	Biased	19.38	20.043	0.6631
65	100	Biased	19.689	20.172	0.4826
66	50	Unbiased	19.57	20.072	0.5022
67	50	Unbiased	19.624	19.745	0.1219
68	50	Unbiased	19.674	20.25	0.5758
69	100	Unbiased	19.905	20.356	0.4512
70	100	Unbiased	19.617	20.466	0.8487
71	100	Unbiased	19.802	20.059	0.2575
72	0	Control	19.276	19.53	0.2541

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.276	19.276	19.276		19.53	19.53	19.53		0.2541	0.2541	0.2541	
50	19.349	19.59	19.691	0.1251	19.745	19.931	20.25	0.19255	0.1219	0.34122	0.5758	0.2168
100	19.38	19.691	19.905	0.18128	20.043	20.206	20.466	0.16978	0.2575	0.51455	0.8487	0.21063

Device Test: 36.29 Iop HS BOOT IIM Interlock Disable 5MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

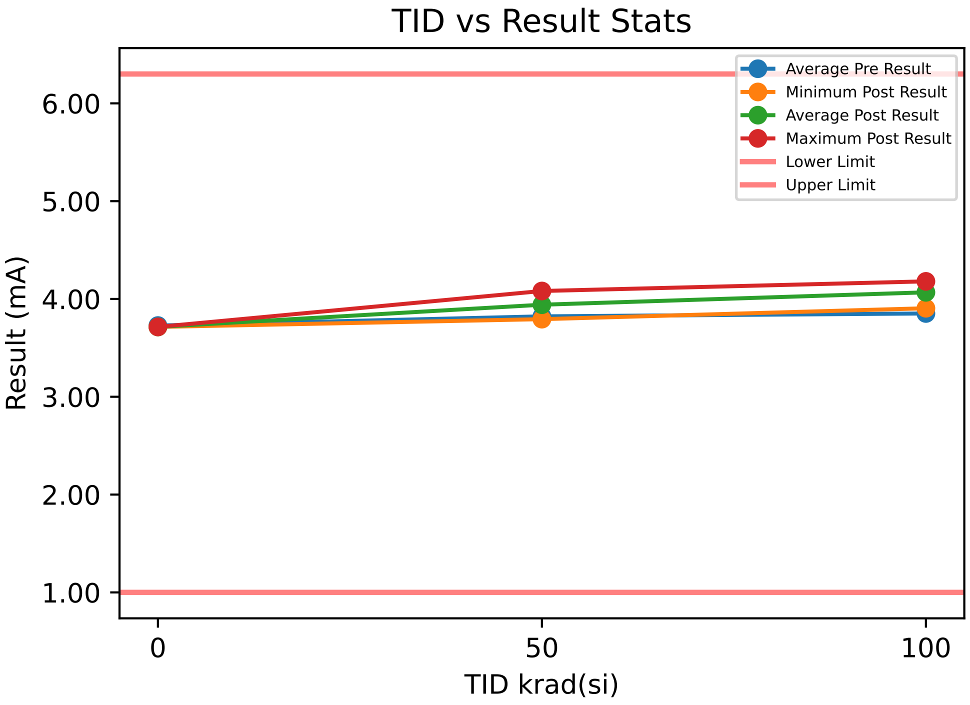
Test Results (Lower Limit = 1.0, Upper Limit = 15.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	12.288	12.626	0.3374
60	50	Biased	12.641	12.461	-0.1794
61	50	Biased	12.3	12.68	0.38
63	100	Biased	12.556	12.974	0.4181
64	100	Biased	12.599	12.799	0.2
65	100	Biased	12.704	12.888	0.1835
66	50	Unbiased	12.812	12.565	-0.2477
67	50	Unbiased	12.598	12.964	0.3663
68	50	Unbiased	12.701	12.436	-0.265
69	100	Unbiased	12.495	12.837	0.3416
70	100	Unbiased	12.705	12.61	-0.0949
71	100	Unbiased	12.603	13.092	0.4891
72	0	Control	12.565	12.311	-0.2536

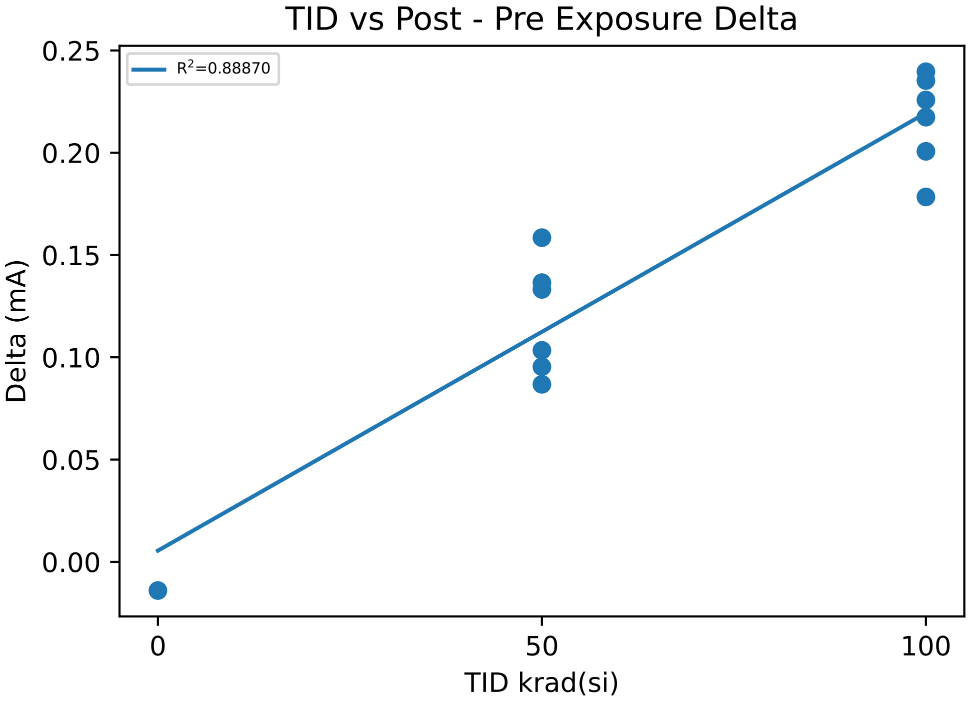
Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.565	12.565	12.565		12.311	12.311	12.311		-0.2536	-0.2536	-0.2536	
50	12.288	12.557	12.812	0.21582	12.436	12.622	12.964	0.19207	-0.265	0.065267	0.38	0.32577
100	12.495	12.61	12.705	0.082555	12.61	12.867	13.092	0.16384	-0.0949	0.25623	0.4891	0.20951

Device Test: 36.3 Iq HS BOOT IIM Interlock VIN_12V



TID vs Result Stats



TID vs Post - Pre Exposure Delta

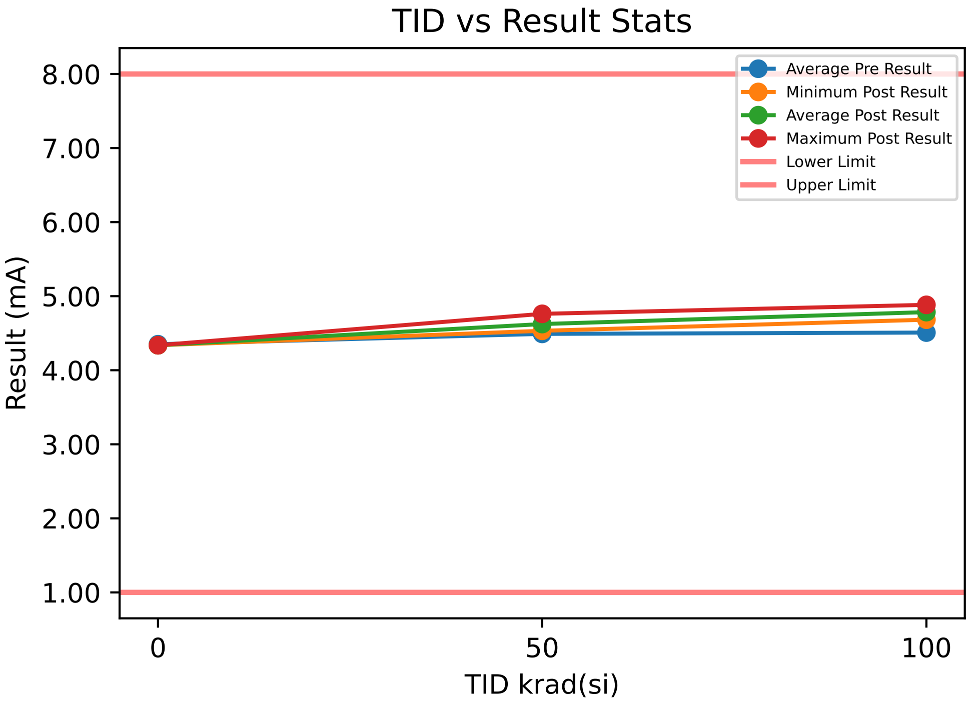
Test Results (Lower Limit = 1.0, Upper Limit = 6.3 (mA))

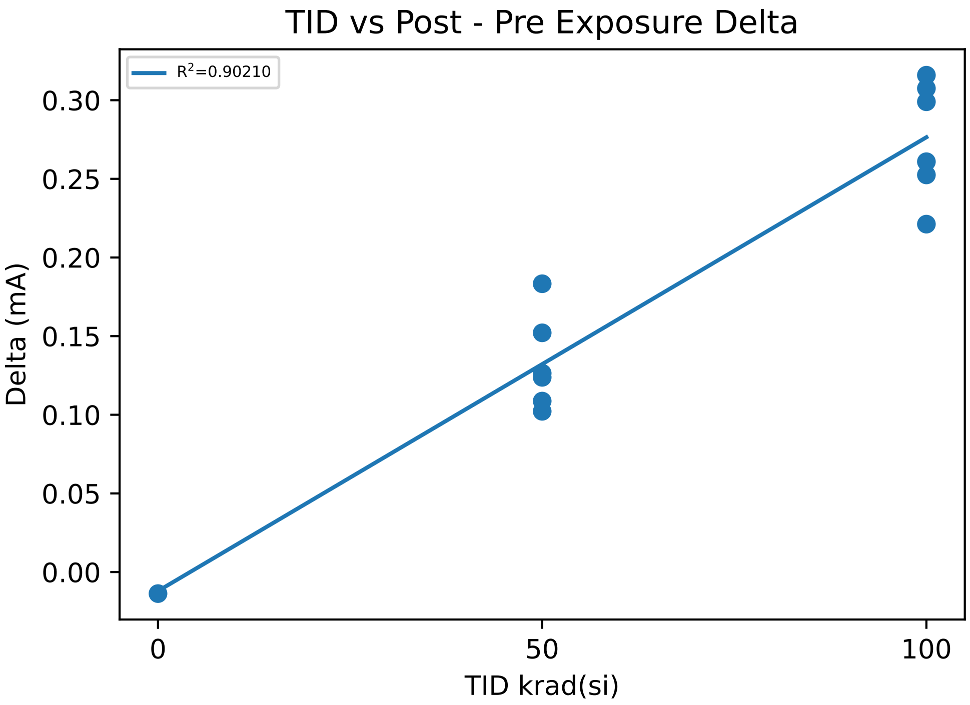
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.6981	3.7935	0.0954
60	50	Biased	3.8132	3.9464	0.1332
61	50	Biased	3.6855	3.844	0.1585
63	100	Biased	3.8367	4.072	0.2353
64	100	Biased	3.7266	3.905	0.1784
65	100	Biased	3.9541	4.1799	0.2258
66	50	Unbiased	3.9946	4.0814	0.0868
67	50	Unbiased	3.9296	4.0661	0.1365
68	50	Unbiased	3.812	3.9154	0.1034
69	100	Unbiased	3.8194	4.0201	0.2007
70	100	Unbiased	3.8676	4.1072	0.2396
71	100	Unbiased	3.905	4.1224	0.2174
72	0	Control	3.7282	3.7142	-0.014

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7282	3.7282	3.7282		3.7142	3.7142	3.7142		-0.014	-0.014	-0.014	
50	3.6855	3.8222	3.9946	0.12291	3.7935	3.9411	4.0814	0.11594	0.0868	0.11897	0.1585	0.027947
100	3.7266	3.8516	3.9541	0.078099	3.905	4.0678	4.1799	0.095809	0.1784	0.2162	0.2396	0.02313

Device Test: 36.4 Iq LS VIN IIM Interlock Disable VIN_12V





Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

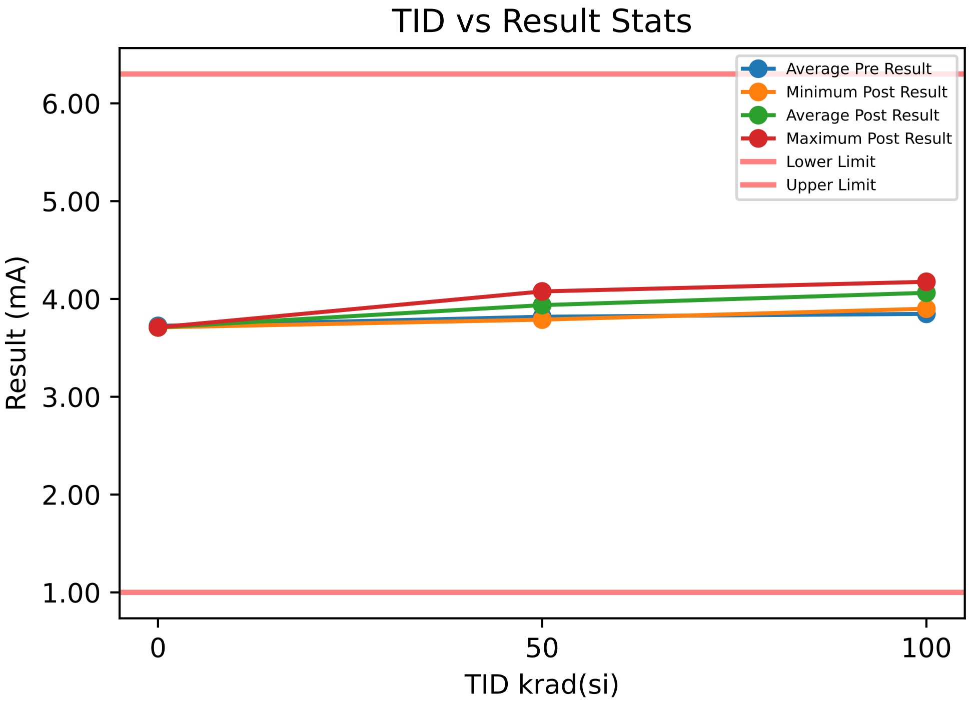
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.4618	4.5882	0.1264
60	50	Biased	4.4625	4.6146	0.1521
61	50	Biased	4.5118	4.6356	0.1238
63	100	Biased	4.5126	4.8285	0.3159
64	100	Biased	4.4677	4.7286	0.2609
65	100	Biased	4.452	4.7045	0.2525
66	50	Unbiased	4.5001	4.6088	0.1087
67	50	Unbiased	4.4302	4.5324	0.1022
68	50	Unbiased	4.5782	4.7615	0.1833
69	100	Unbiased	4.5754	4.8829	0.3075
70	100	Unbiased	4.5817	4.8807	0.299
71	100	Unbiased	4.4611	4.6823	0.2212
72	0	Control	4.3511	4.3374	-0.0137

Test Statistics (mA)

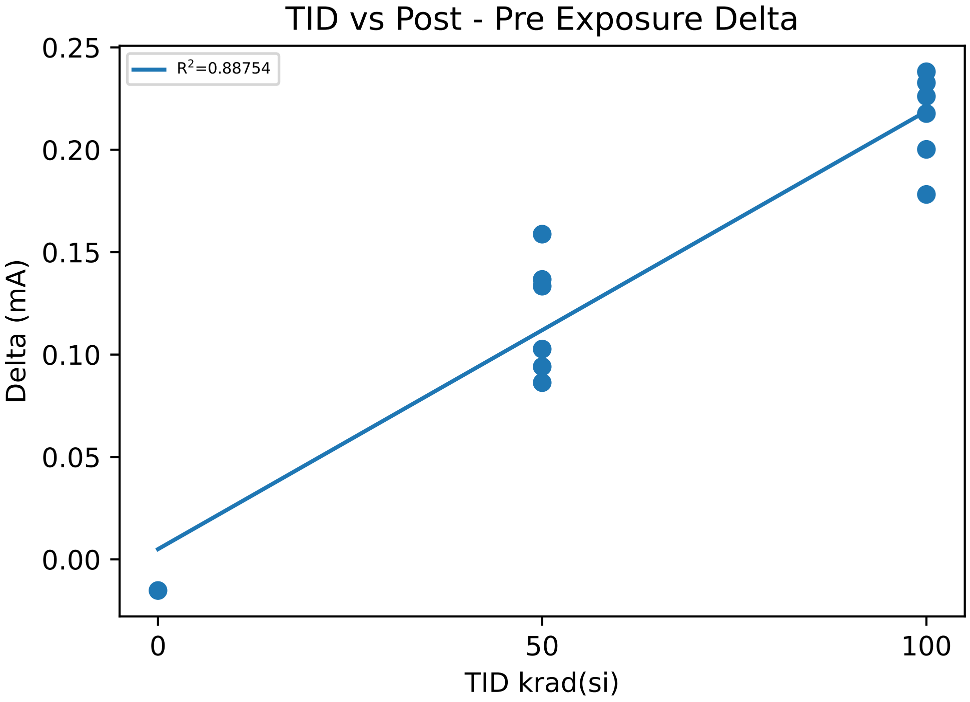
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3511	4.3511	4.3511		4.3374	4.3374	4.3374		-0.0137	-0.0137	-0.0137	
50	4.4302	4.4908	4.5782	0.051924	4.5324	4.6235	4.7615	0.076198	0.1022	0.13275	0.1833	0.030205
100	4.452	4.5084	4.5817	0.058231	4.6823	4.7846	4.8829	0.09038	0.2212	0.27617	0.3159	0.037139

Device Test: 36.5 Iq HS BOOT IIM Interlock Disable VIN_12V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



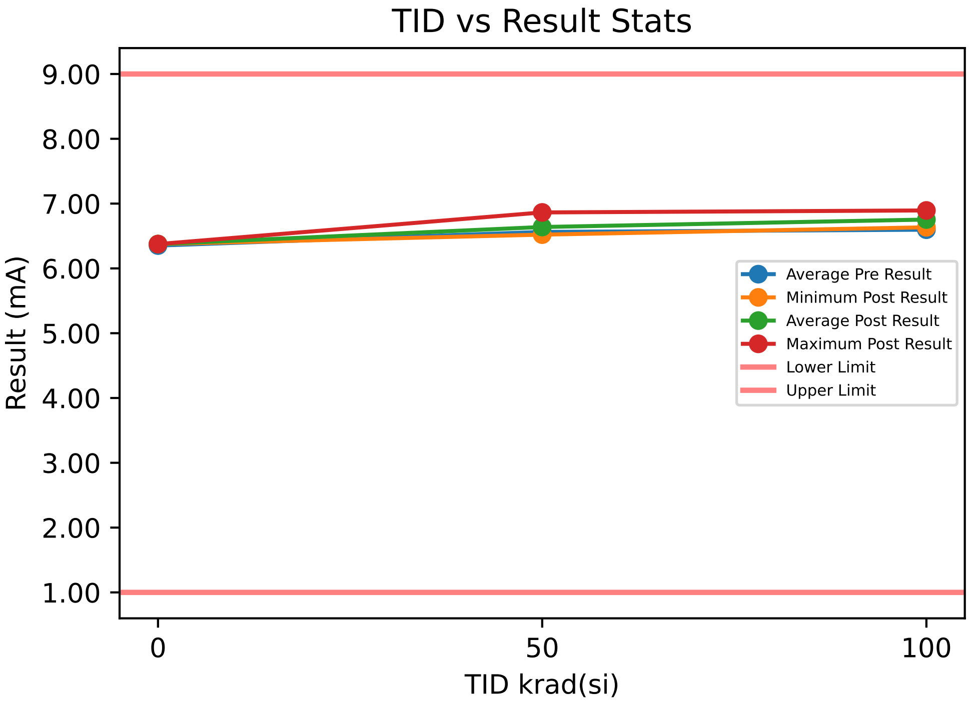
Test Results (Lower Limit = 1.0, Upper Limit = 6.3 (mA))

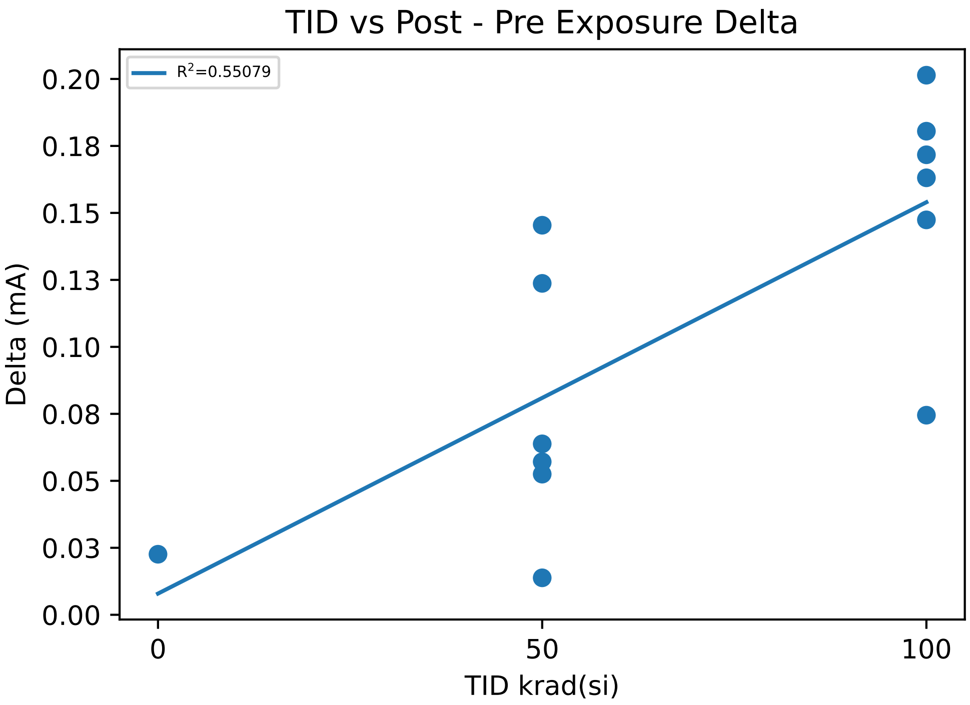
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.6945	3.7886	0.0941
60	50	Biased	3.8083	3.9417	0.1334
61	50	Biased	3.6817	3.8405	0.1588
63	100	Biased	3.8335	4.0662	0.2327
64	100	Biased	3.7223	3.9005	0.1782
65	100	Biased	3.9495	4.1756	0.2261
66	50	Unbiased	3.9908	4.0771	0.0863
67	50	Unbiased	3.9262	4.0629	0.1367
68	50	Unbiased	3.8085	3.9112	0.1027
69	100	Unbiased	3.8154	4.0156	0.2002
70	100	Unbiased	3.8642	4.1023	0.2381
71	100	Unbiased	3.9005	4.1182	0.2177
72	0	Control	3.7248	3.7096	-0.0152

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7248	3.7248	3.7248		3.7096	3.7096	3.7096		-0.0152	-0.0152	-0.0152	
50	3.6817	3.8183	3.9908	0.12295	3.7886	3.937	4.0771	0.11619	0.0863	0.11867	0.1588	0.028492
100	3.7223	3.8476	3.9495	0.077966	3.9005	4.0631	4.1756	0.095847	0.1782	0.2155	0.2381	0.02258

Device Test: 36.6 Iop LS VIN PWM 500kHz VIN_12V





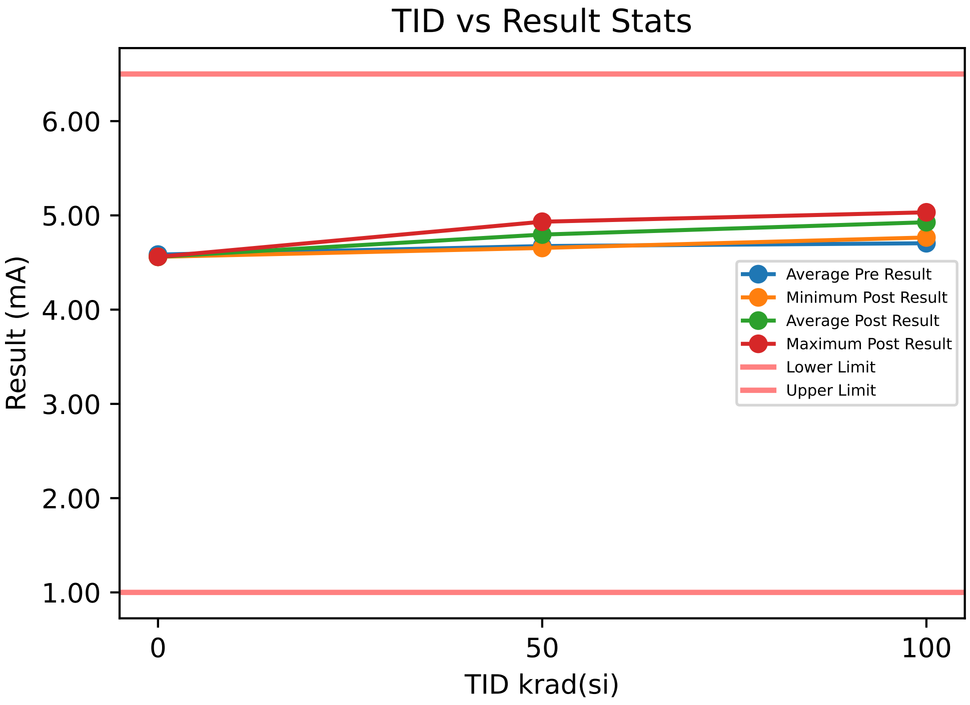
Test Results (Lower Limit = 1.0, Upper Limit = 9.0 (mA))

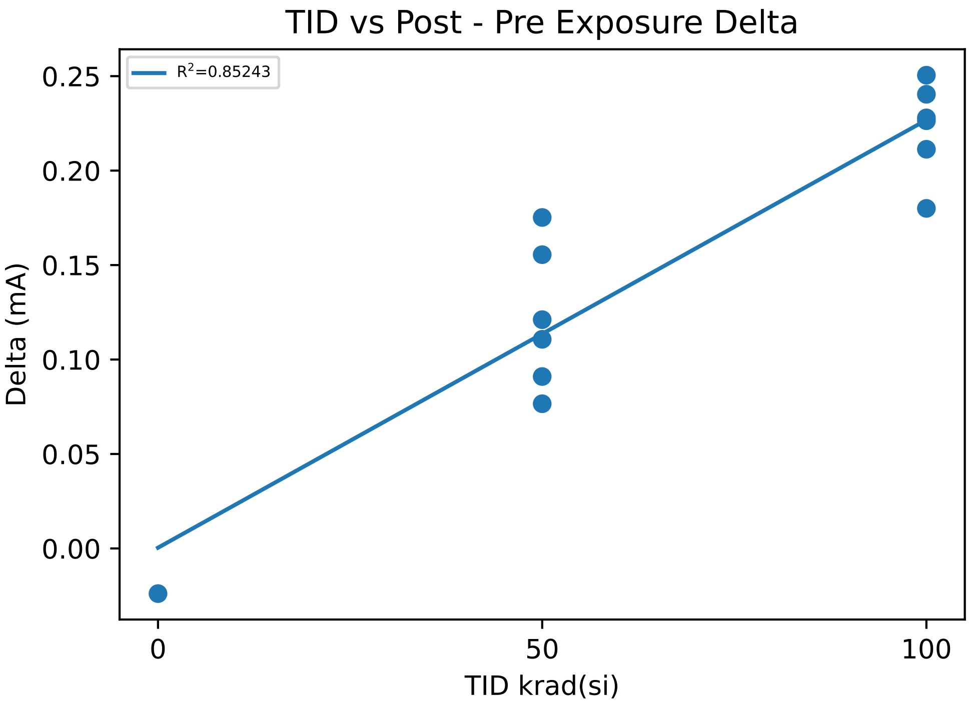
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.4697	6.5268	0.0571
60	50	Biased	6.4399	6.5636	0.1237
61	50	Biased	6.5617	6.6142	0.0525
63	100	Biased	6.6453	6.817	0.1717
64	100	Biased	6.4536	6.6341	0.1805
65	100	Biased	6.5382	6.6856	0.1474
66	50	Unbiased	6.6792	6.743	0.0638
67	50	Unbiased	6.5072	6.521	0.0138
68	50	Unbiased	6.7184	6.8638	0.1454
69	100	Unbiased	6.6781	6.8412	0.1631
70	100	Unbiased	6.693	6.8944	0.2014
71	100	Unbiased	6.5754	6.6499	0.0745
72	0	Control	6.3525	6.3751	0.0226

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.3525	6.3525	6.3525		6.3751	6.3751	6.3751		0.0226	0.0226	0.0226	
50	6.4399	6.5627	6.7184	0.11369	6.521	6.6387	6.8638	0.13723	0.0138	0.07605	0.1454	0.049028
100	6.4536	6.5973	6.693	0.092318	6.6341	6.7537	6.8944	0.11061	0.0745	0.15643	0.2014	0.043985

Device Test: 36.7 Iop HS BOOT PWM 500kHz VIN_12V





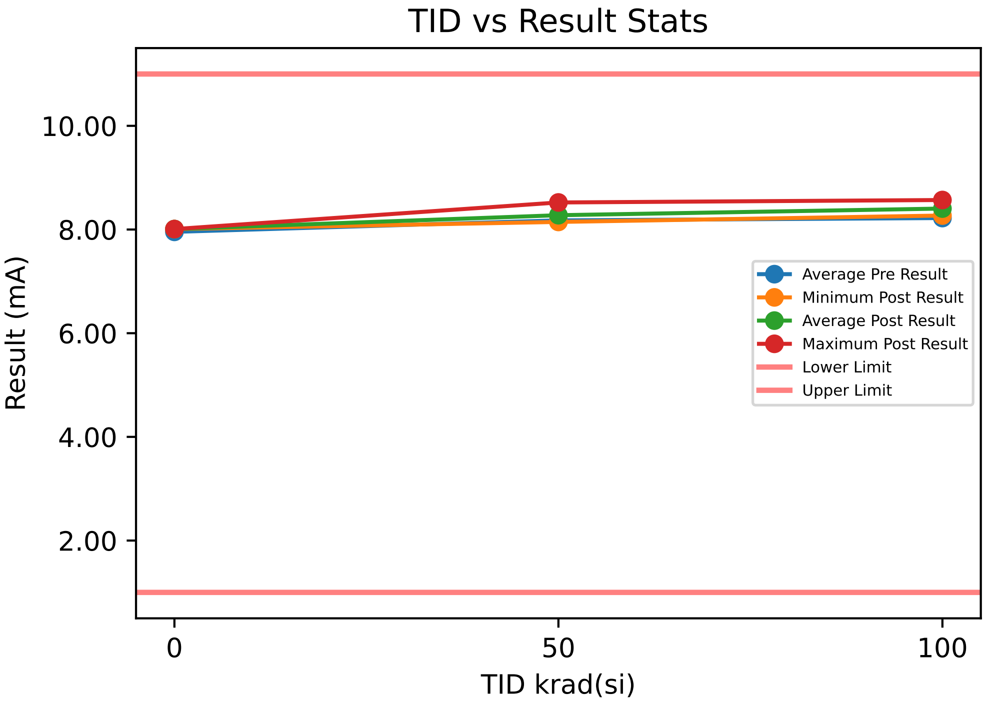
Test Results (Lower Limit = 1.0, Upper Limit = 6.5 (mA))

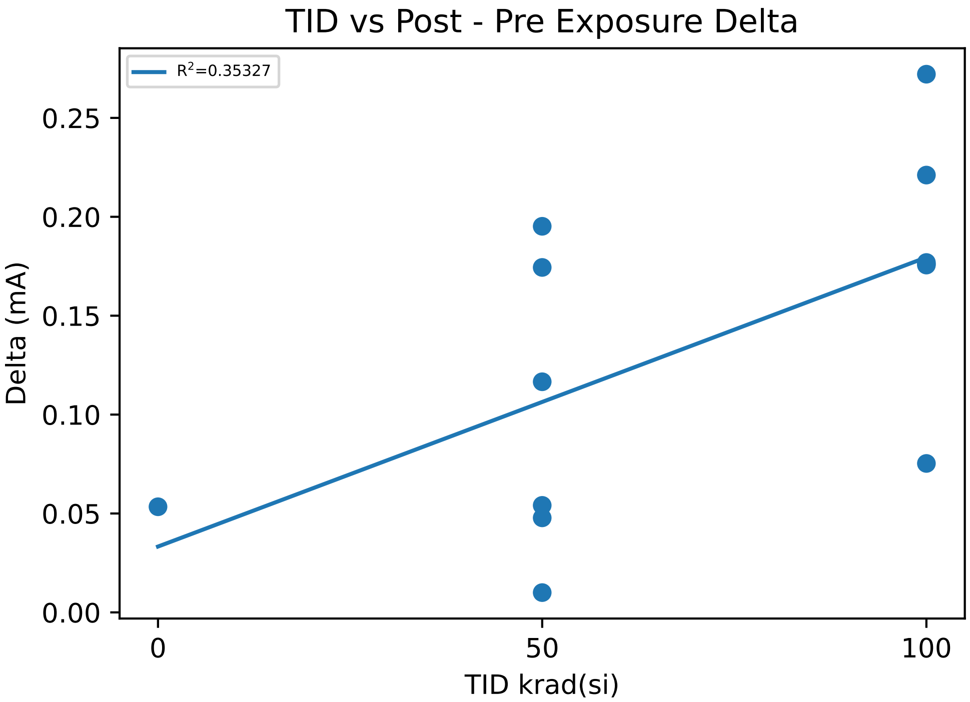
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.5436	4.6543	0.1107
60	50	Biased	4.6671	4.7882	0.1211
61	50	Biased	4.5333	4.7085	0.1752
63	100	Biased	4.6864	4.9369	0.2505
64	100	Biased	4.5857	4.7657	0.18
65	100	Biased	4.8061	5.0325	0.2264
66	50	Unbiased	4.8524	4.929	0.0766
67	50	Unbiased	4.7772	4.9327	0.1555
68	50	Unbiased	4.6735	4.7645	0.091
69	100	Unbiased	4.6693	4.8806	0.2113
70	100	Unbiased	4.7244	4.9523	0.2279
71	100	Unbiased	4.7543	4.9947	0.2404
72	0	Control	4.5842	4.5603	-0.0239

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5842	4.5842	4.5842		4.5603	4.5603	4.5603		-0.0239	-0.0239	-0.0239	
50	4.5333	4.6745	4.8524	0.12596	4.6543	4.7962	4.9327	0.11416	0.0766	0.12168	0.1752	0.03769
100	4.5857	4.7044	4.8061	0.075998	4.7657	4.9271	5.0325	0.094469	0.18	0.22275	0.2505	0.02482

Device Test: 36.8 Iop LS VIN PWM 1MHz VIN_12V





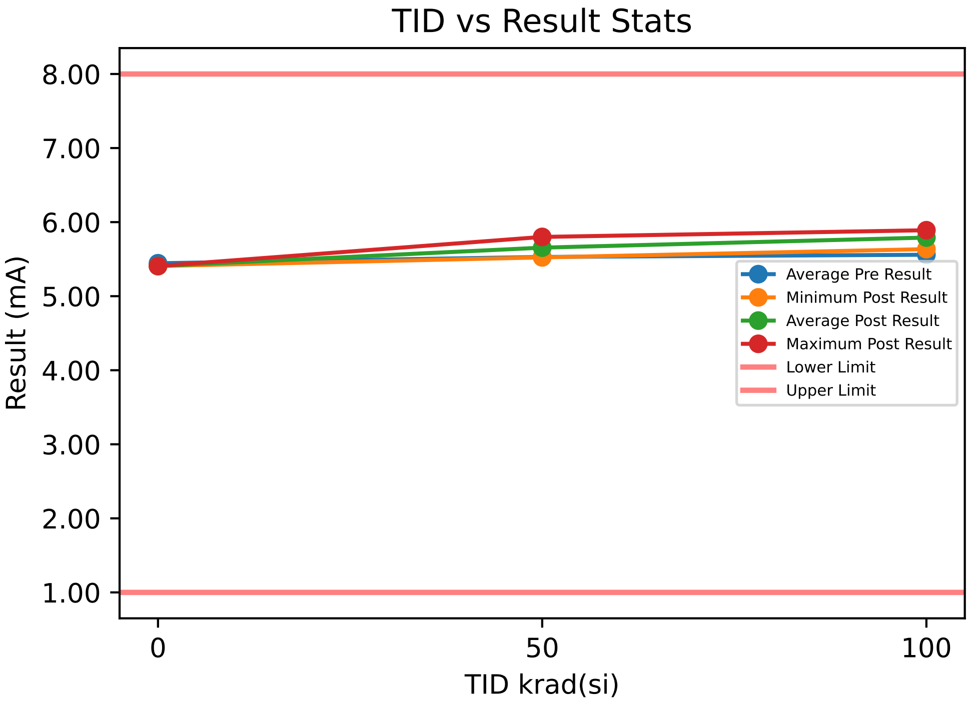
Test Results (Lower Limit = 1.0, Upper Limit = 11.0 (mA))

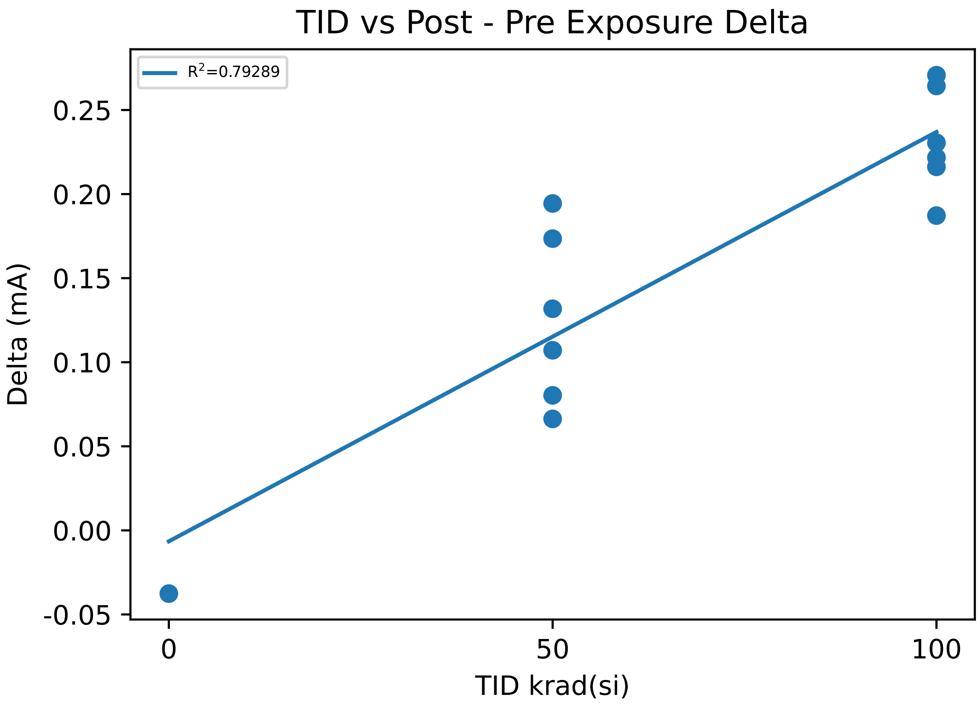
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	8.0966	8.1507	0.0541
60	50	Biased	8.0328	8.2072	0.1744
61	50	Biased	8.1883	8.2361	0.0478
63	100	Biased	8.2737	8.4493	0.1756
64	100	Biased	8.0488	8.2699	0.2211
65	100	Biased	8.1697	8.3466	0.1769
66	50	Unbiased	8.2768	8.3934	0.1166
67	50	Unbiased	8.1364	8.1464	0.01
68	50	Unbiased	8.3267	8.5219	0.1952
69	100	Unbiased	8.322	8.4981	0.1761
70	100	Unbiased	8.297	8.5691	0.2721
71	100	Unbiased	8.2169	8.2922	0.0753
72	0	Control	7.9551	8.0085	0.0534

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.9551	7.9551	7.9551		8.0085	8.0085	8.0085		0.0534	0.0534	0.0534	
50	8.0328	8.1763	8.3267	0.11082	8.1464	8.2759	8.5219	0.15038	0.01	0.099683	0.1952	0.074572
100	8.0488	8.2213	8.322	0.10105	8.2699	8.4042	8.5691	0.11995	0.0753	0.18285	0.2721	0.065006

Device Test: 36.9 Iop HS BOOT PWM 1MHz VIN_12V





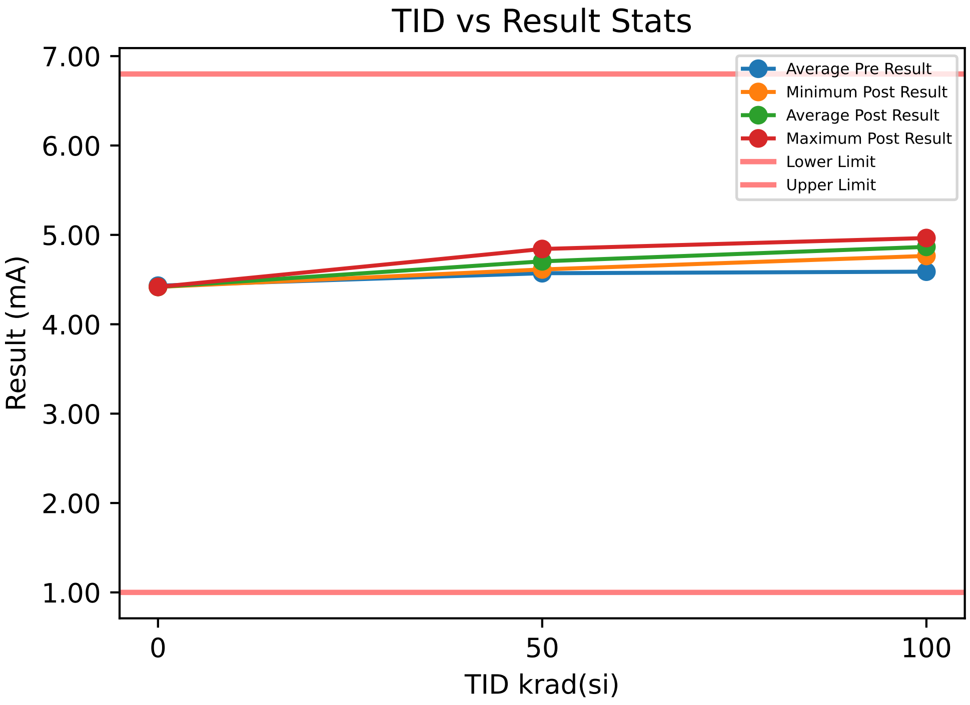
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

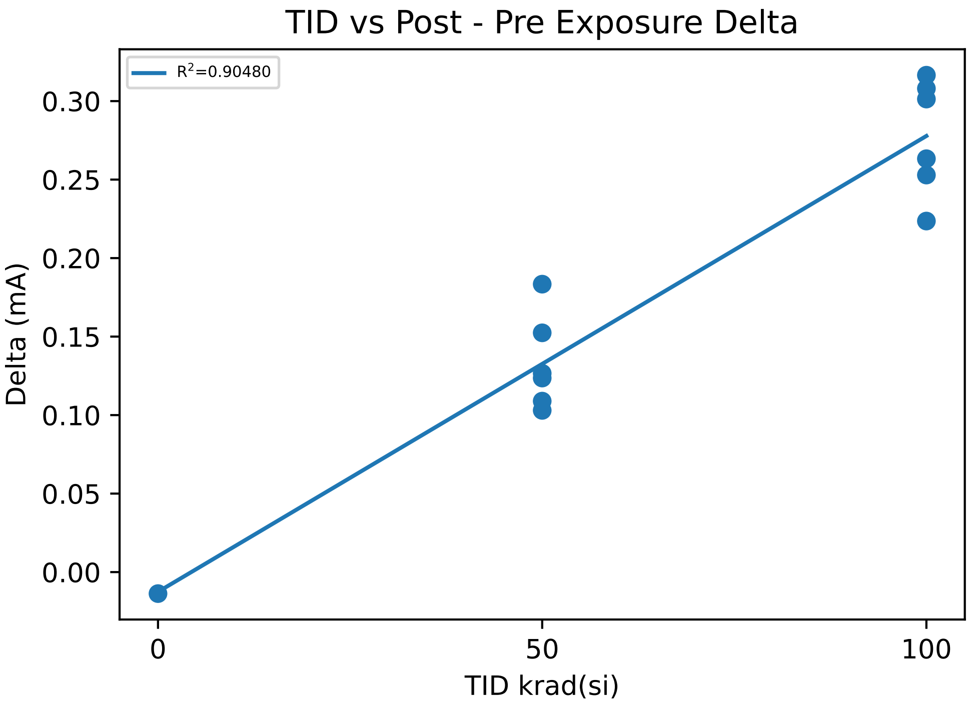
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.3917	5.5235	0.1318
60	50	Biased	5.5261	5.6332	0.1071
61	50	Biased	5.3821	5.5765	0.1944
63	100	Biased	5.5365	5.8072	0.2707
64	100	Biased	5.4479	5.6351	0.1872
65	100	Biased	5.6599	5.8904	0.2305
66	50	Unbiased	5.7116	5.7779	0.0663
67	50	Unbiased	5.6264	5.7999	0.1735
68	50	Unbiased	5.5393	5.6196	0.0803
69	100	Unbiased	5.522	5.7437	0.2217
70	100	Unbiased	5.5828	5.799	0.2162
71	100	Unbiased	5.607	5.8713	0.2643
72	0	Control	5.4445	5.4069	-0.0376

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4445	5.4445	5.4445		5.4069	5.4069	5.4069		-0.0376	-0.0376	-0.0376	
50	5.3821	5.5295	5.7116	0.12913	5.5235	5.6551	5.7999	0.11071	0.0663	0.12557	0.1944	0.050945
100	5.4479	5.5593	5.6599	0.07385	5.6351	5.7911	5.8904	0.092948	0.1872	0.23177	0.2707	0.031323

Device Test: 37.0 Iq LS VIN PWM VIN_14V





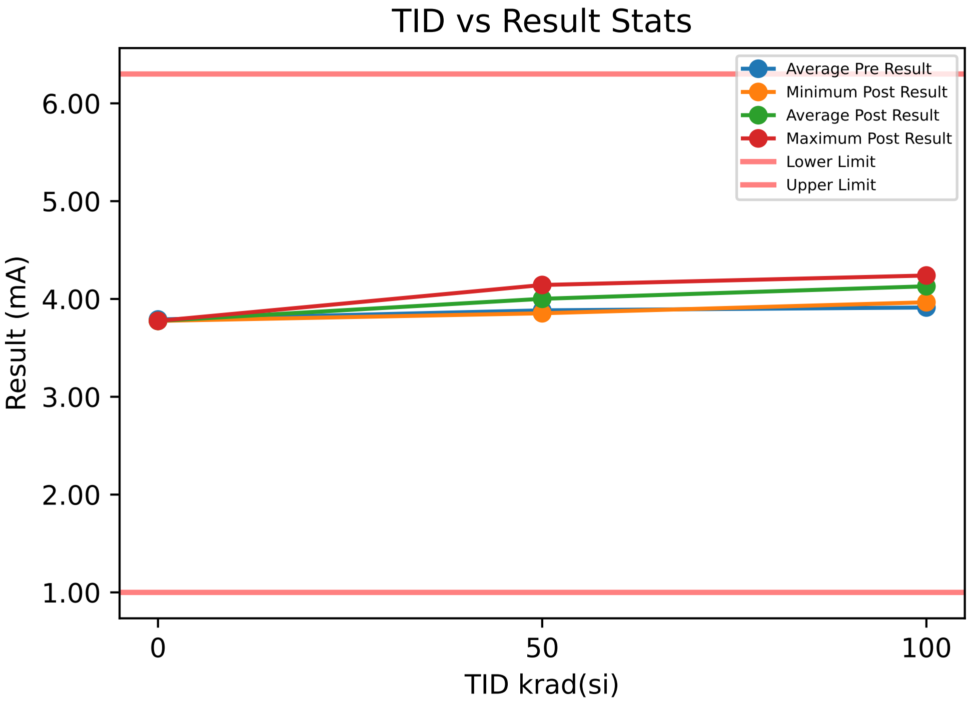
Test Results (Lower Limit = 1.0, Upper Limit = 6.8 (mA))

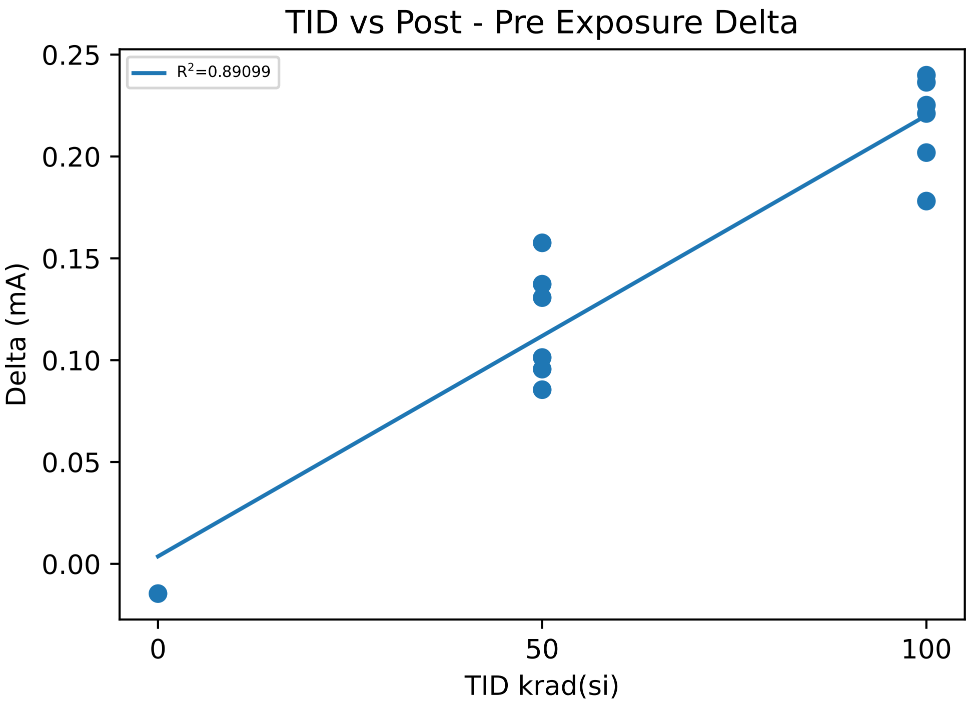
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.5416	4.6682	0.1266
60	50	Biased	4.5432	4.6956	0.1524
61	50	Biased	4.5919	4.7155	0.1236
63	100	Biased	4.5922	4.9087	0.3165
64	100	Biased	4.5456	4.8089	0.2633
65	100	Biased	4.5321	4.785	0.2529
66	50	Unbiased	4.5802	4.6891	0.1089
67	50	Unbiased	4.5102	4.6132	0.103
68	50	Unbiased	4.6588	4.8422	0.1834
69	100	Unbiased	4.6568	4.9648	0.308
70	100	Unbiased	4.6622	4.9635	0.3013
71	100	Unbiased	4.5409	4.7645	0.2236
72	0	Control	4.4315	4.4178	-0.0137

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4315	4.4315	4.4315		4.4178	4.4178	4.4178		-0.0137	-0.0137	-0.0137	
50	4.5102	4.571	4.6588	0.052085	4.6132	4.704	4.8422	0.076224	0.103	0.13298	0.1834	0.030089
100	4.5321	4.5883	4.6622	0.058987	4.7645	4.8659	4.9648	0.090791	0.2236	0.2776	0.3165	0.036687

Device Test: 37.1 Iq HS BOOT PWM VIN_14V





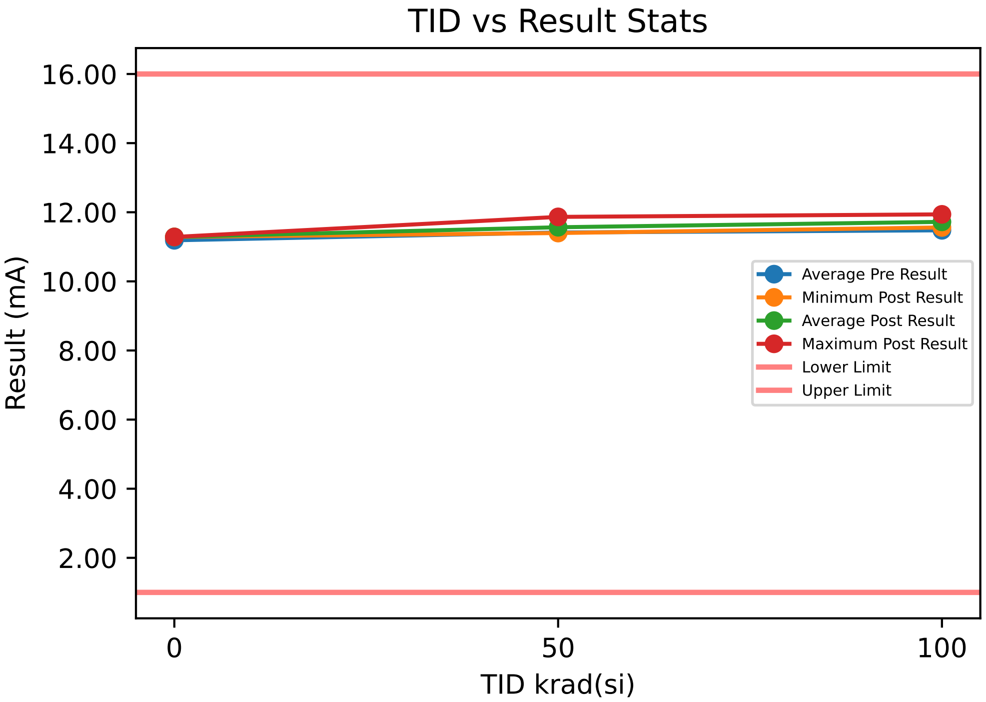
Test Results (Lower Limit = 1.0, Upper Limit = 6.3 (mA))

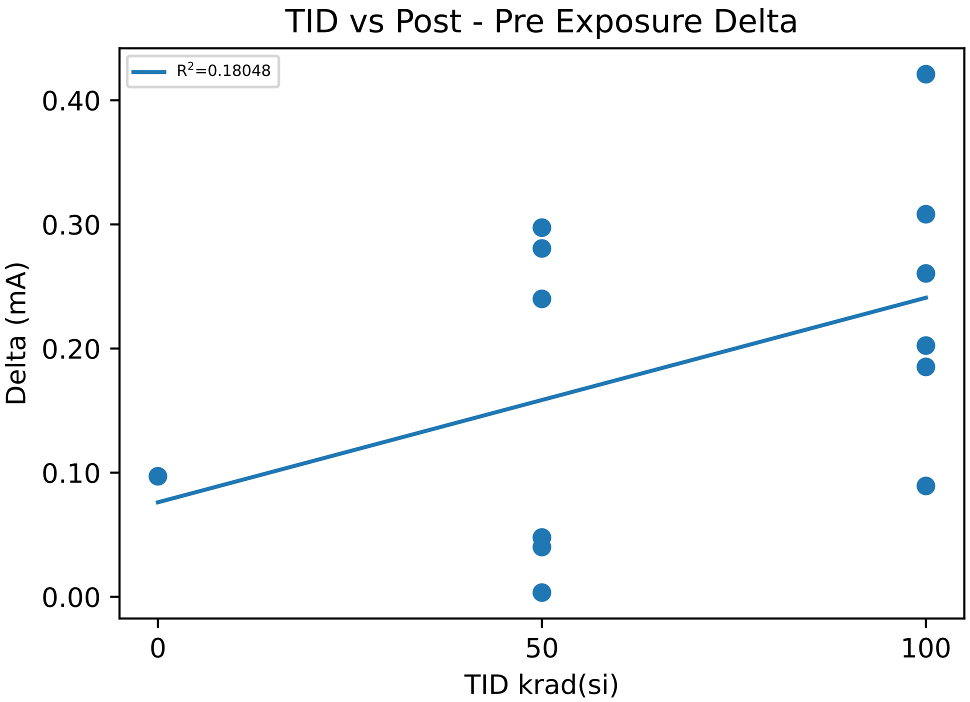
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.7582	3.8538	0.0956
60	50	Biased	3.8743	4.005	0.1307
61	50	Biased	3.7445	3.9021	0.1576
63	100	Biased	3.8972	4.1336	0.2364
64	100	Biased	3.7881	3.9662	0.1781
65	100	Biased	4.0147	4.2399	0.2252
66	50	Unbiased	4.0574	4.1429	0.0855
67	50	Unbiased	3.9915	4.1288	0.1373
68	50	Unbiased	3.8756	3.9769	0.1013
69	100	Unbiased	3.8803	4.0822	0.2019
70	100	Unbiased	3.9307	4.1706	0.2399
71	100	Unbiased	3.9651	4.1862	0.2211
72	0	Control	3.7903	3.7757	-0.0146

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7903	3.7903	3.7903		3.7757	3.7757	3.7757		-0.0146	-0.0146	-0.0146	
50	3.7445	3.8836	4.0574	0.12416	3.8538	4.0016	4.1429	0.11706	0.0855	0.118	0.1576	0.028067
100	3.7881	3.9127	4.0147	0.077832	3.9662	4.1298	4.2399	0.09593	0.1781	0.2171	0.2399	0.023349

Device Test: 37.10 Iop LS VIN PWM 2MHz VIN_14V





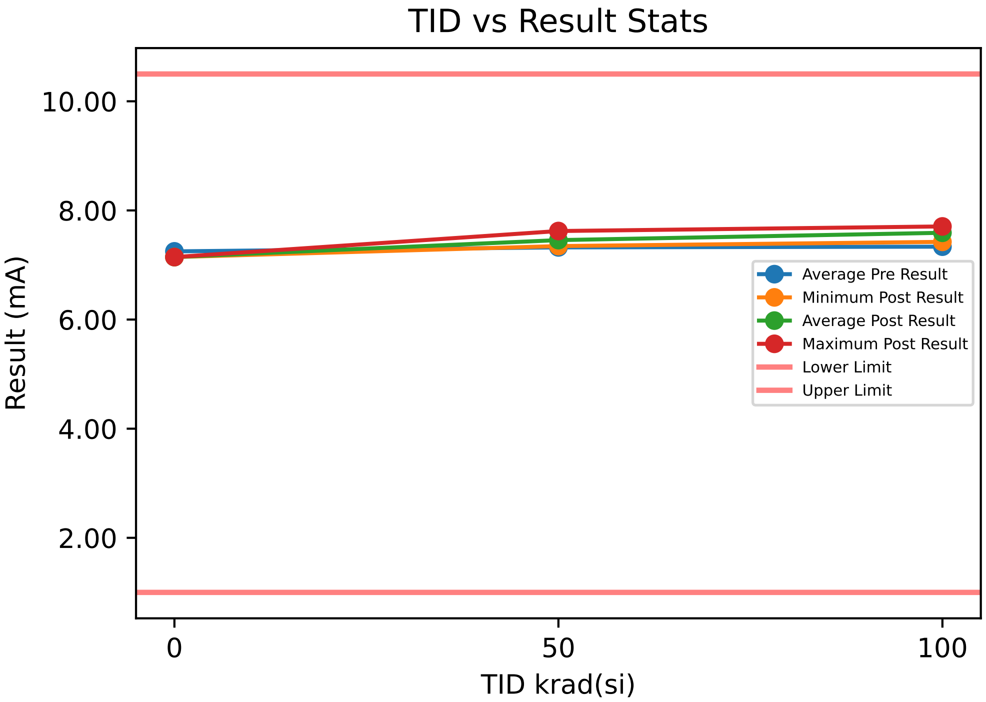
Test Results (Lower Limit = 1.0, Upper Limit = 16.0 (mA))

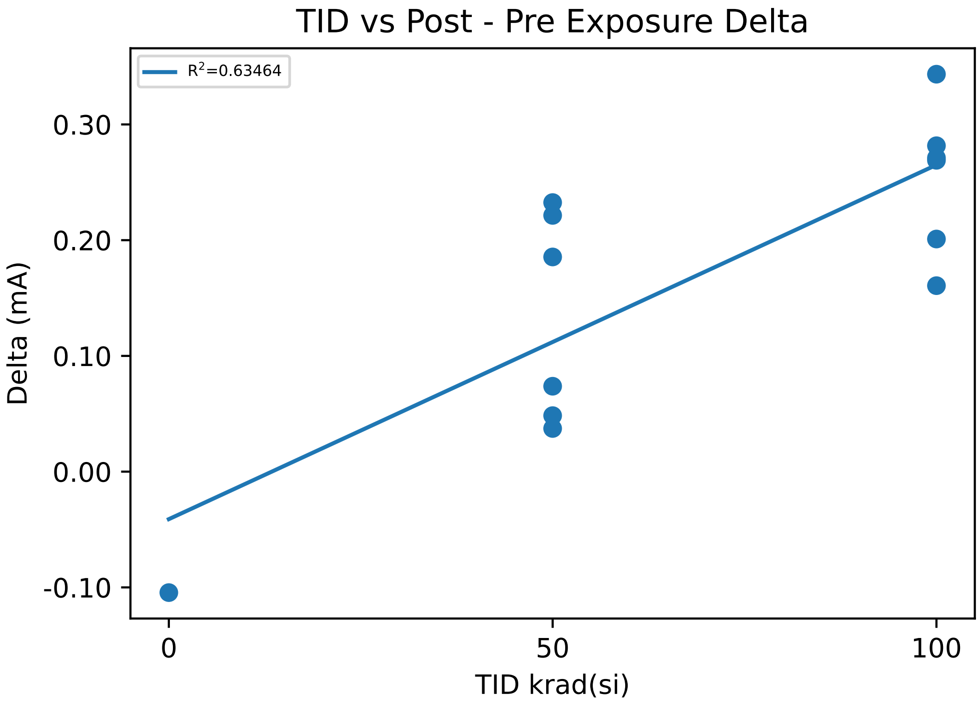
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	11.358	11.406	0.0478
60	50	Biased	11.242	11.522	0.2806
61	50	Biased	11.444	11.484	0.0401
63	100	Biased	11.536	11.721	0.1852
64	100	Biased	11.252	11.56	0.3082
65	100	Biased	11.438	11.698	0.2605
66	50	Unbiased	11.477	11.717	0.24
67	50	Unbiased	11.395	11.398	0.0034
68	50	Unbiased	11.568	11.866	0.2974
69	100	Unbiased	11.611	11.813	0.2024
70	100	Unbiased	11.518	11.939	0.421
71	100	Unbiased	11.507	11.596	0.0893
72	0	Control	11.188	11.285	0.0971

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.188	11.188	11.188		11.285	11.285	11.285		0.0971	0.0971	0.0971	
50	11.242	11.414	11.568	0.11122	11.398	11.566	11.866	0.18703	0.0034	0.15155	0.2974	0.13482
100	11.252	11.477	11.611	0.1234	11.56	11.721	11.939	0.13992	0.0893	0.24443	0.421	0.11388

Device Test: 37.11 Iop HS BOOT PWM 2MHz VIN_14V





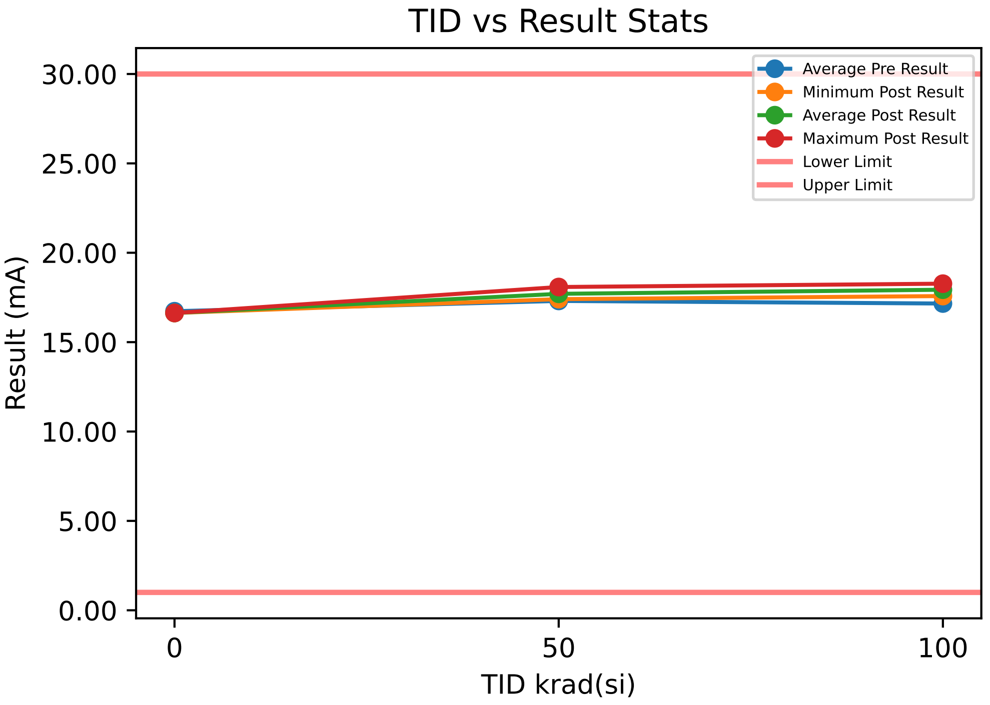
Test Results (Lower Limit = 1.0, Upper Limit = 10.5 (mA))

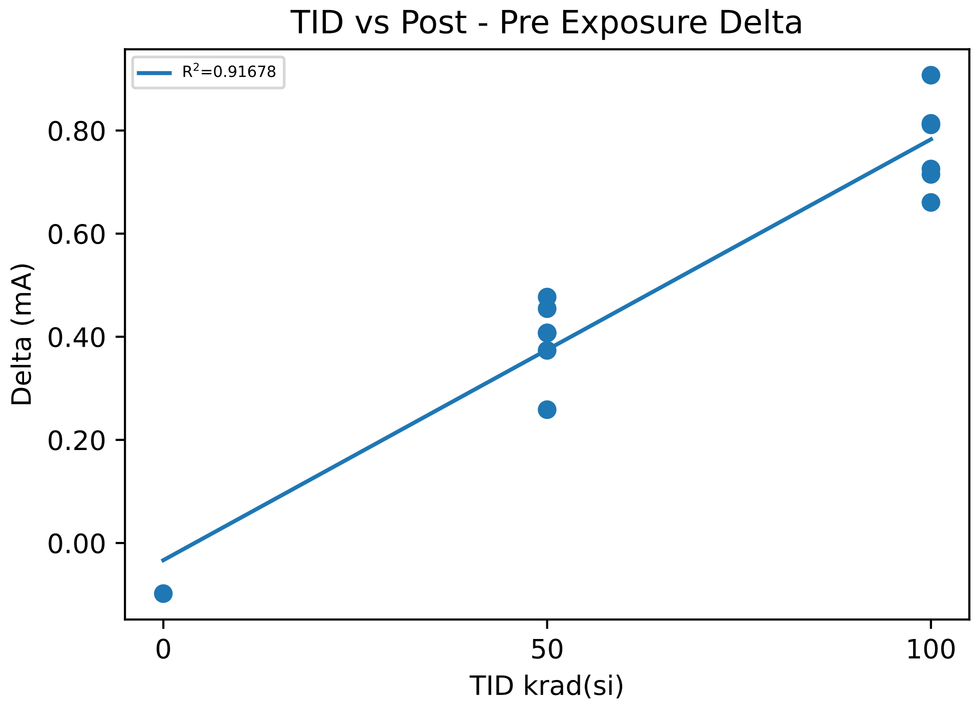
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.1611	7.3466	0.1855
60	50	Biased	7.3286	7.4024	0.0738
61	50	Biased	7.1602	7.3927	0.2325
63	100	Biased	7.3213	7.6029	0.2816
64	100	Biased	7.2635	7.4242	0.1607
65	100	Biased	7.4157	7.6847	0.269
66	50	Unbiased	7.5236	7.5609	0.0373
67	50	Unbiased	7.4009	7.6223	0.2214
68	50	Unbiased	7.3606	7.409	0.0484
69	100	Unbiased	7.2747	7.5458	0.2711
70	100	Unbiased	7.3762	7.5772	0.201
71	100	Unbiased	7.3631	7.7065	0.3434
72	0	Control	7.2497	7.1452	-0.1045

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2497	7.2497	7.2497		7.1452	7.1452	7.1452		-0.1045	-0.1045	-0.1045	
50	7.1602	7.3225	7.5236	0.14175	7.3466	7.4556	7.6223	0.10929	0.0373	0.13315	0.2325	0.089768
100	7.2635	7.3357	7.4157	0.059887	7.4242	7.5902	7.7065	0.10229	0.1607	0.25447	0.3434	0.064473

Device Test: 37.12 Iop LS VIN PWM 5MHz VIN_14V





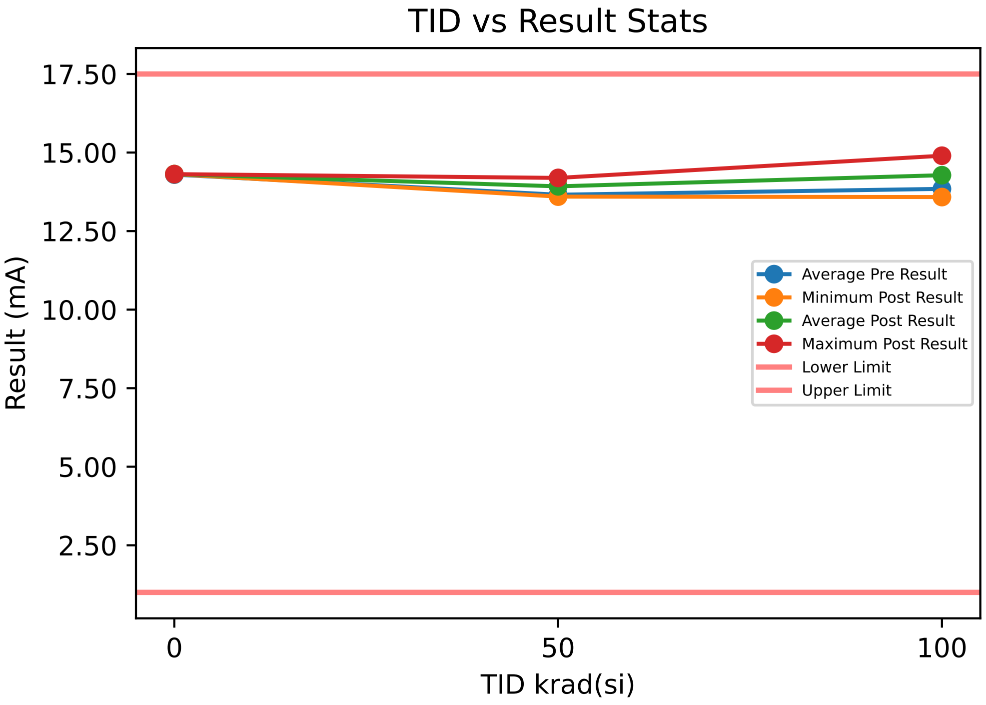
Test Results (Lower Limit = 1.0,
Upper Limit = 30.0 (mA))

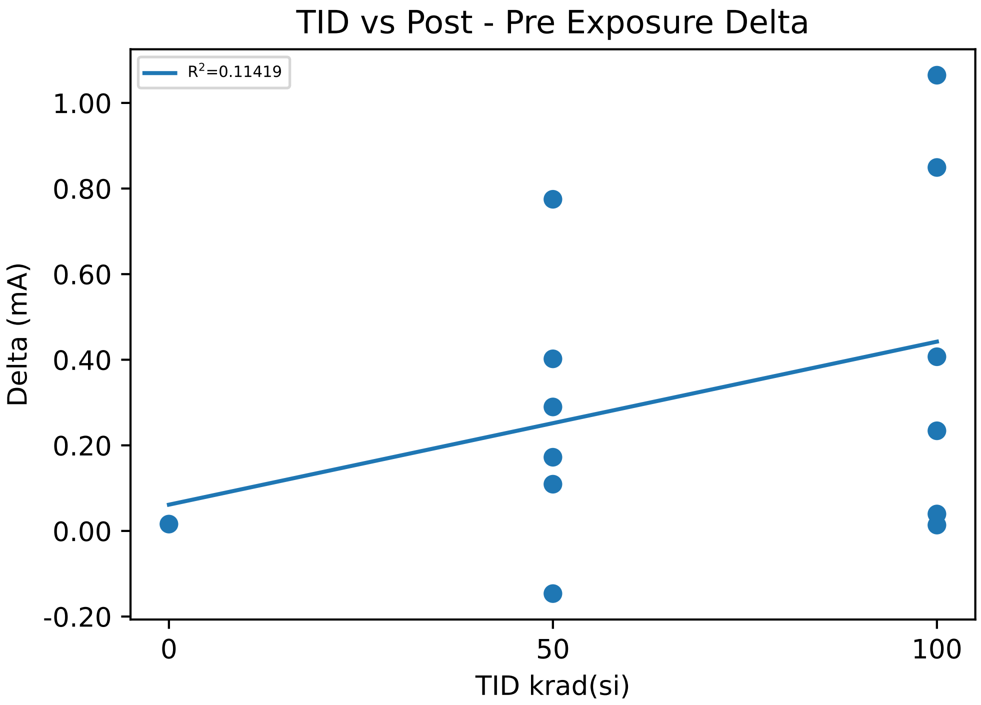
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	17.287	17.694	0.4074
60	50	Biased	17.224	17.632	0.4075
61	50	Biased	17.193	17.648	0.4545
63	100	Biased	17.326	18.14	0.8139
64	100	Biased	16.948	17.663	0.7149
65	100	Biased	17.13	17.79	0.6605
66	50	Unbiased	17.492	17.751	0.2586
67	50	Unbiased	16.927	17.404	0.477
68	50	Unbiased	17.71	18.084	0.3736
69	100	Unbiased	17.363	18.27	0.9073
70	100	Unbiased	17.426	18.151	0.7254
71	100	Unbiased	16.766	17.577	0.811
72	0	Control	16.729	16.631	-0.0981

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	16.729	16.729	16.729		16.631	16.631	16.631		-0.0981	-0.0981	-0.0981	
50	16.927	17.306	17.71	0.26879	17.404	17.702	18.084	0.2212	0.2586	0.39643	0.477	0.076974
100	16.766	17.16	17.426	0.26074	17.577	17.932	18.27	0.29106	0.6605	0.77217	0.9073	0.088822

Device Test: 37.13 Iop HS BOOT PWM 5MHz VIN_14V





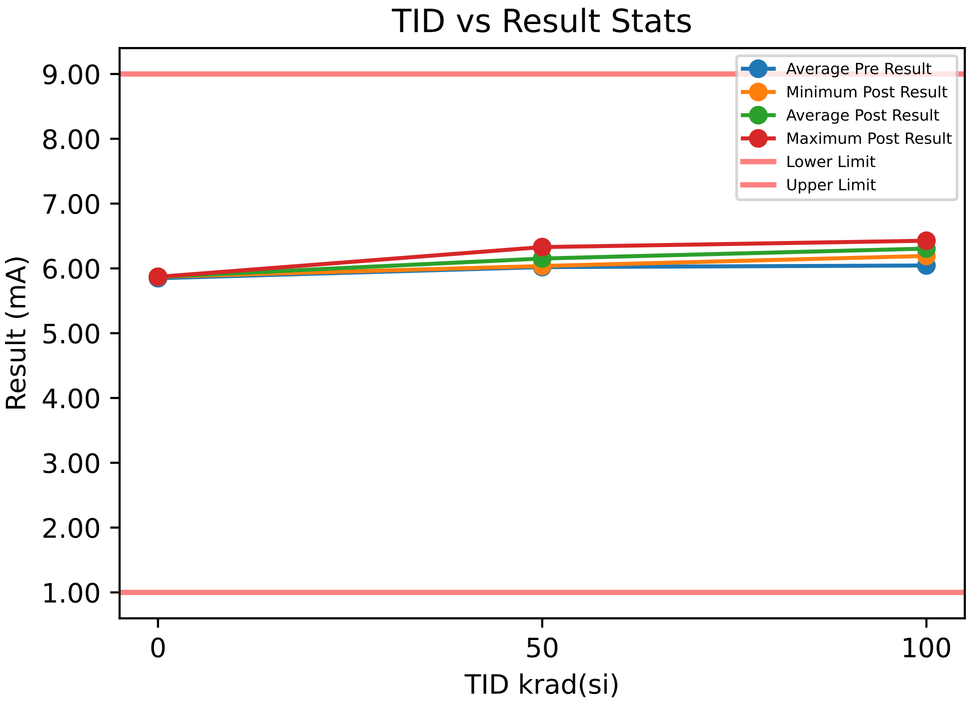
Test Results (Lower Limit = 1.0, Upper Limit = 17.5 (mA))

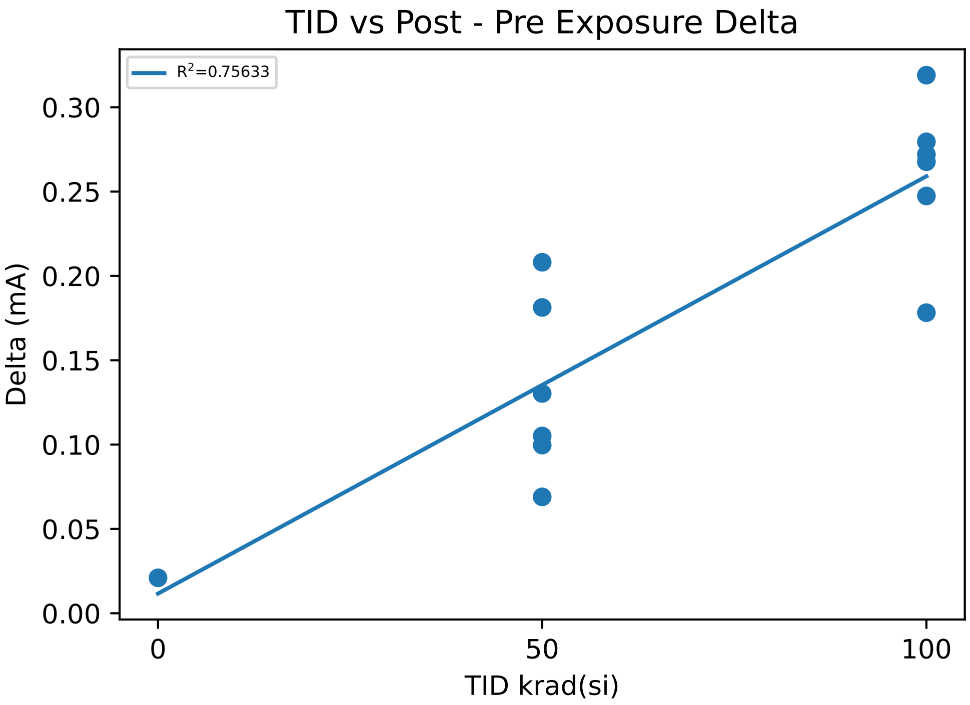
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	13.456	13.746	0.2897
60	50	Biased	13.79	14.192	0.4021
61	50	Biased	13.399	14.174	0.7749
63	100	Biased	14.05	14.899	0.8492
64	100	Biased	13.644	14.708	1.0648
65	100	Biased	14.3	14.314	0.0137
66	50	Unbiased	13.488	13.597	0.1092
67	50	Unbiased	14.303	14.156	-0.1464
68	50	Unbiased	13.506	13.678	0.1722
69	100	Unbiased	13.334	13.741	0.407
70	100	Unbiased	13.544	13.583	0.0396
71	100	Unbiased	14.194	14.428	0.234
72	0	Control	14.297	14.313	0.016

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	14.297	14.297	14.297		14.313	14.313	14.313		0.016	0.016	0.016	
50	13.399	13.657	14.303	0.34429	13.597	13.924	14.192	0.27841	-0.1464	0.26695	0.7749	0.31033
100	13.334	13.844	14.3	0.39079	13.583	14.279	14.899	0.5226	0.0137	0.43472	1.0648	0.43433

Device Test: 37.14 Iop LS VIN IIM Interlock 500kHz VIN_14V





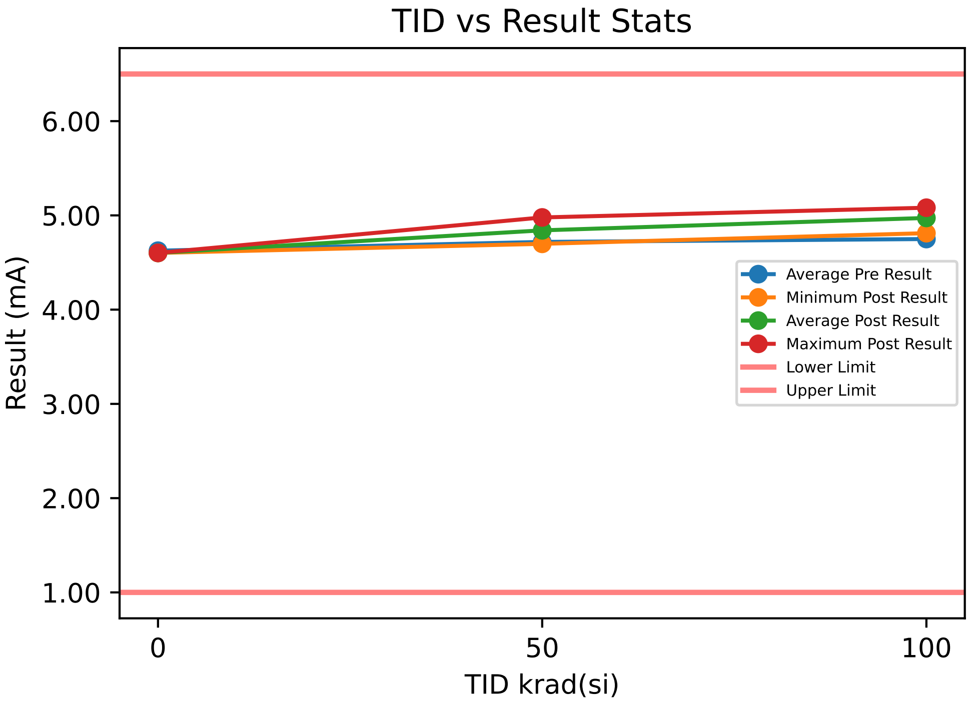
Test Results (Lower Limit = 1.0, Upper Limit = 9.0 (mA))

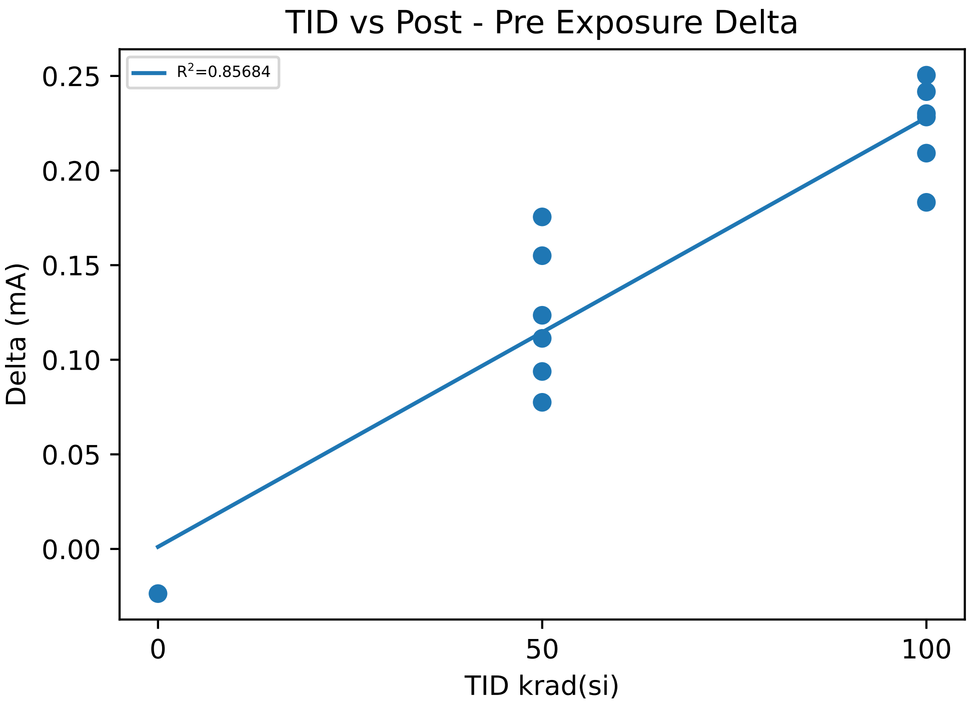
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.9832	6.0883	0.1051
60	50	Biased	5.9514	6.1327	0.1813
61	50	Biased	6.0466	6.1463	0.0997
63	100	Biased	6.0665	6.346	0.2795
64	100	Biased	5.9607	6.2327	0.272
65	100	Biased	5.9945	6.2419	0.2474
66	50	Unbiased	6.05	6.1803	0.1303
67	50	Unbiased	5.9679	6.0369	0.069
68	50	Unbiased	6.1207	6.3288	0.2081
69	100	Unbiased	6.1261	6.3938	0.2677
70	100	Unbiased	6.1082	6.4272	0.319
71	100	Unbiased	6.0138	6.192	0.1782
72	0	Control	5.8485	5.8695	0.021

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8485	5.8485	5.8485		5.8695	5.8695	5.8695		0.021	0.021	0.021	
50	5.9514	6.02	6.1207	0.064067	6.0369	6.1522	6.3288	0.099769	0.069	0.13225	0.2081	0.05284
100	5.9607	6.045	6.1261	0.065824	6.192	6.3056	6.4272	0.096411	0.1782	0.26063	0.319	0.046716

Device Test: 37.15 Iop HS BOOT IIM Interlock 500kHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

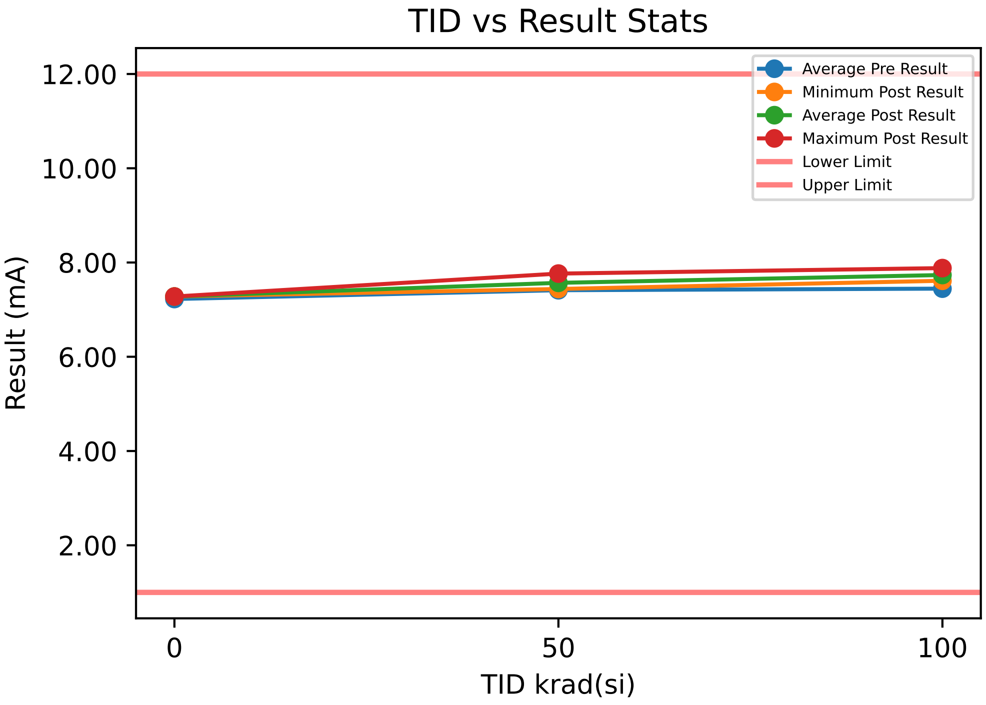
Test Results (Lower Limit = 1.0, Upper Limit = 6.5 (mA))

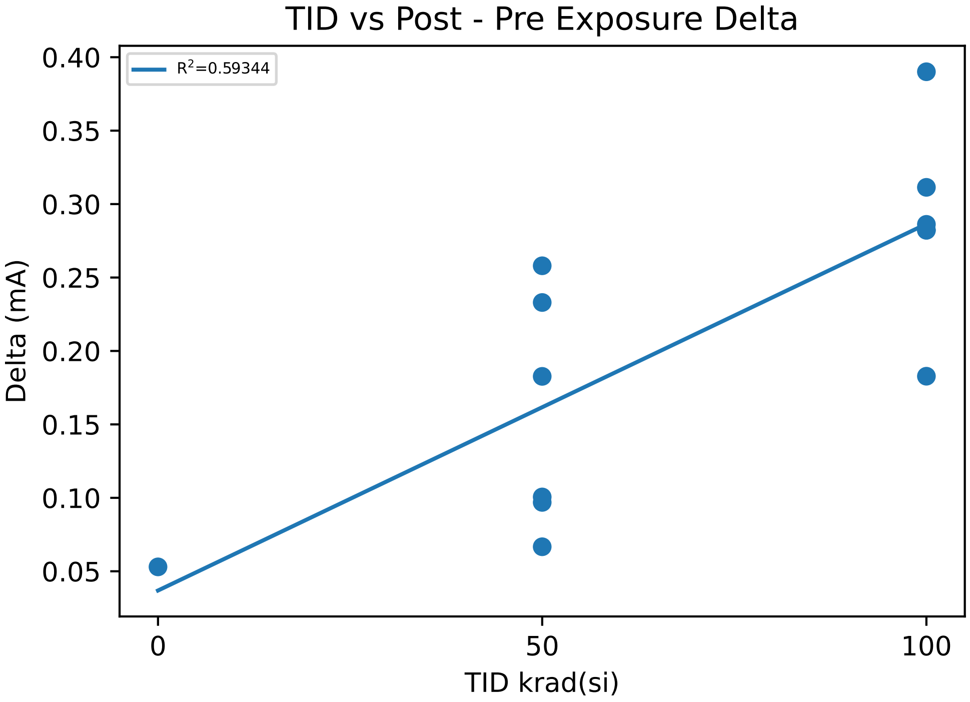
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.5868	4.6981	0.1113
60	50	Biased	4.7105	4.834	0.1235
61	50	Biased	4.5755	4.751	0.1755
63	100	Biased	4.7326	4.983	0.2504
64	100	Biased	4.6281	4.8113	0.1832
65	100	Biased	4.853	5.0813	0.2283
66	50	Unbiased	4.8958	4.9733	0.0775
67	50	Unbiased	4.8231	4.9781	0.155
68	50	Unbiased	4.7187	4.8125	0.0938
69	100	Unbiased	4.7152	4.9244	0.2092
70	100	Unbiased	4.7674	4.9975	0.2301
71	100	Unbiased	4.7977	5.0394	0.2417
72	0	Control	4.6254	4.6018	-0.0236

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6254	4.6254	4.6254		4.6018	4.6018	4.6018		-0.0236	-0.0236	-0.0236	
50	4.5755	4.7184	4.8958	0.12668	4.6981	4.8412	4.9781	0.11461	0.0775	0.12277	0.1755	0.036986
100	4.6281	4.749	4.853	0.076882	4.8113	4.9728	5.0813	0.095233	0.1832	0.22382	0.2504	0.024288

Device Test: 37.16 Iop LS VIN IIM Interlock 1MHz VIN_14V





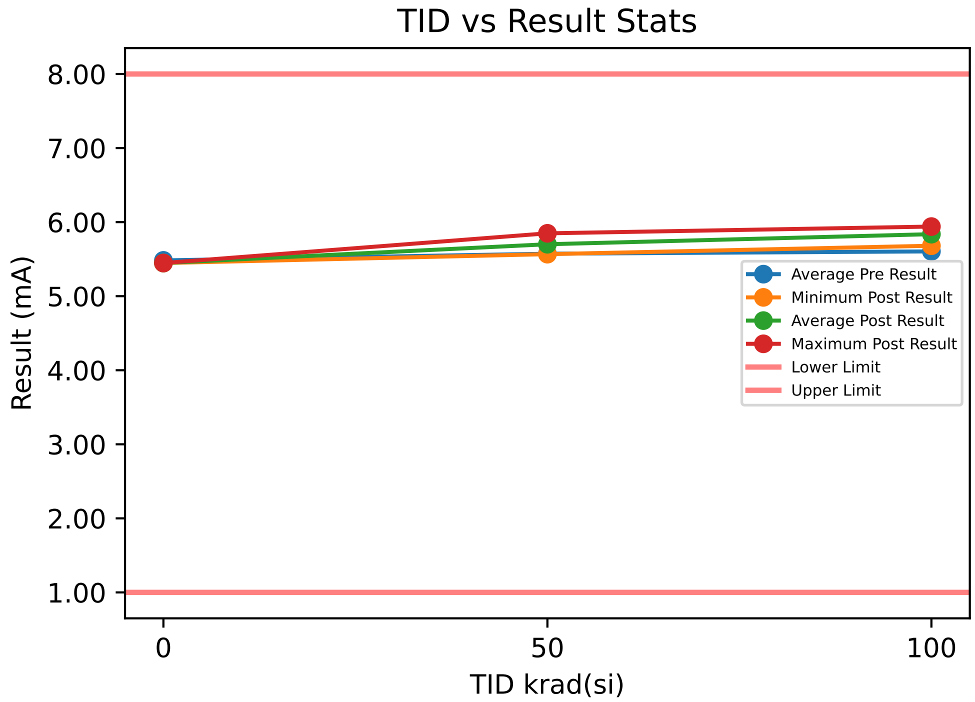
Test Results (Lower Limit = 1.0, Upper Limit = 12.0 (mA))

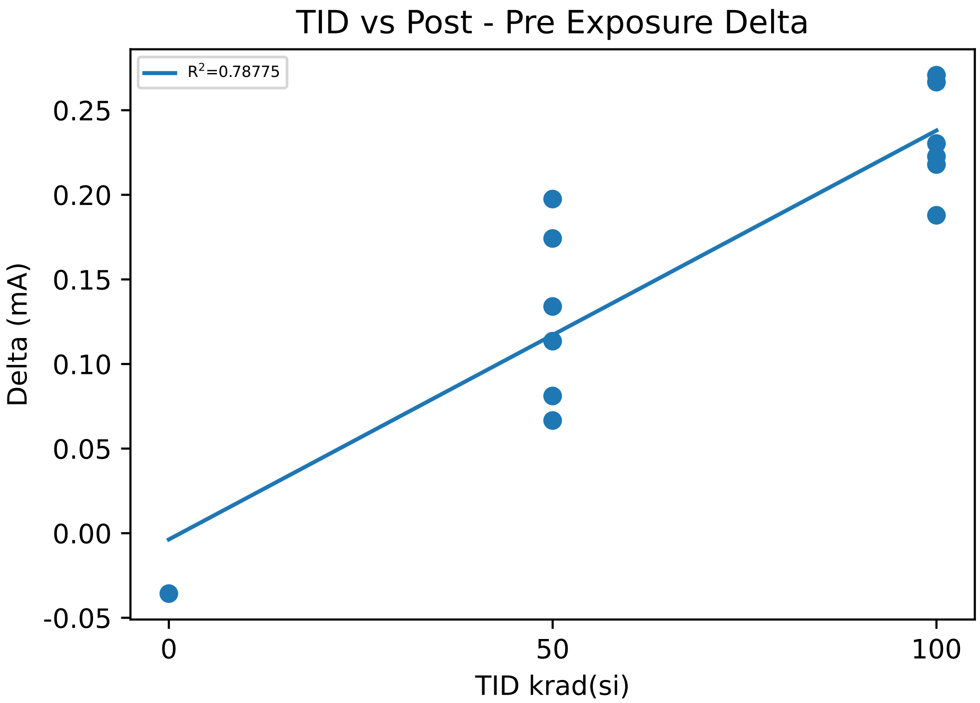
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.3896	7.4902	0.1006
60	50	Biased	7.3252	7.5582	0.233
61	50	Biased	7.4481	7.545	0.0969
63	100	Biased	7.47	7.7562	0.2862
64	100	Biased	7.3373	7.6487	0.3114
65	100	Biased	7.4024	7.6846	0.2822
66	50	Unbiased	7.43	7.6127	0.1827
67	50	Unbiased	7.3719	7.4386	0.0667
68	50	Unbiased	7.5069	7.7649	0.258
69	100	Unbiased	7.5422	7.8244	0.2822
70	100	Unbiased	7.4913	7.8814	0.3901
71	100	Unbiased	7.4298	7.6126	0.1828
72	0	Control	7.2253	7.2783	0.053

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2253	7.2253	7.2253		7.2783	7.2783	7.2783		0.053	0.053	0.053	
50	7.3252	7.412	7.5069	0.063682	7.4386	7.5683	7.7649	0.1133	0.0667	0.15632	0.258	0.079475
100	7.3373	7.4455	7.5422	0.071917	7.6126	7.7346	7.8814	0.10473	0.1828	0.28915	0.3901	0.066485

Device Test: 37.17 Iop HS BOOT IIM Interlock 1MHz VIN_14V





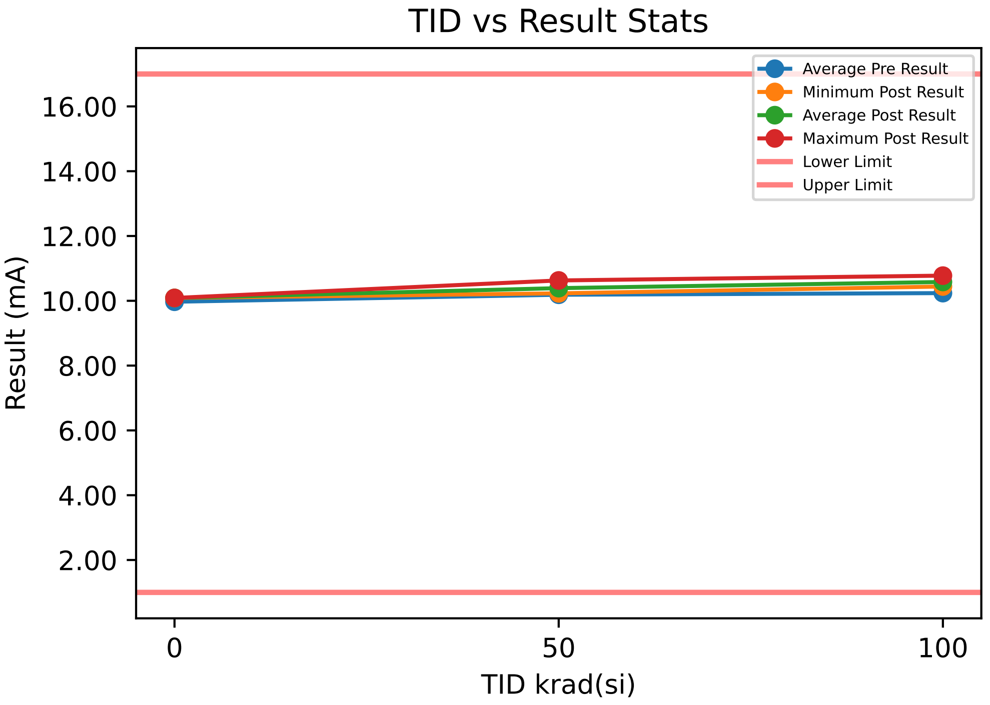
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

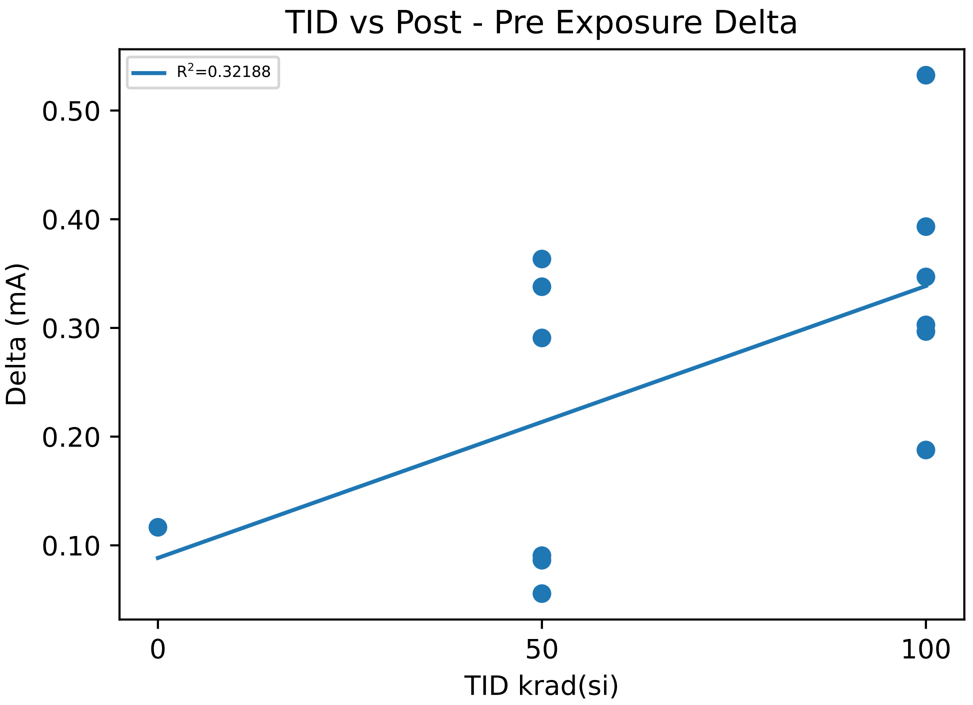
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.4331	5.5671	0.134
60	50	Biased	5.5682	5.6817	0.1135
61	50	Biased	5.4236	5.6211	0.1975
63	100	Biased	5.5831	5.8538	0.2707
64	100	Biased	5.4931	5.681	0.1879
65	100	Biased	5.7094	5.9397	0.2303
66	50	Unbiased	5.7559	5.8225	0.0666
67	50	Unbiased	5.6744	5.8486	0.1742
68	50	Unbiased	5.5838	5.6649	0.0811
69	100	Unbiased	5.5664	5.7891	0.2227
70	100	Unbiased	5.626	5.8439	0.2179
71	100	Unbiased	5.6492	5.9158	0.2666
72	0	Control	5.4831	5.4474	-0.0357

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4831	5.4831	5.4831		5.4474	5.4474	5.4474		-0.0357	-0.0357	-0.0357	
50	5.4236	5.5732	5.7559	0.13097	5.5671	5.701	5.8486	0.11184	0.0666	0.12782	0.1975	0.051343
100	5.4931	5.6045	5.7094	0.074544	5.681	5.8372	5.9397	0.093506	0.1879	0.23268	0.2707	0.031385

Device Test: 37.18 Iop LS VIN IIM Interlock 2MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

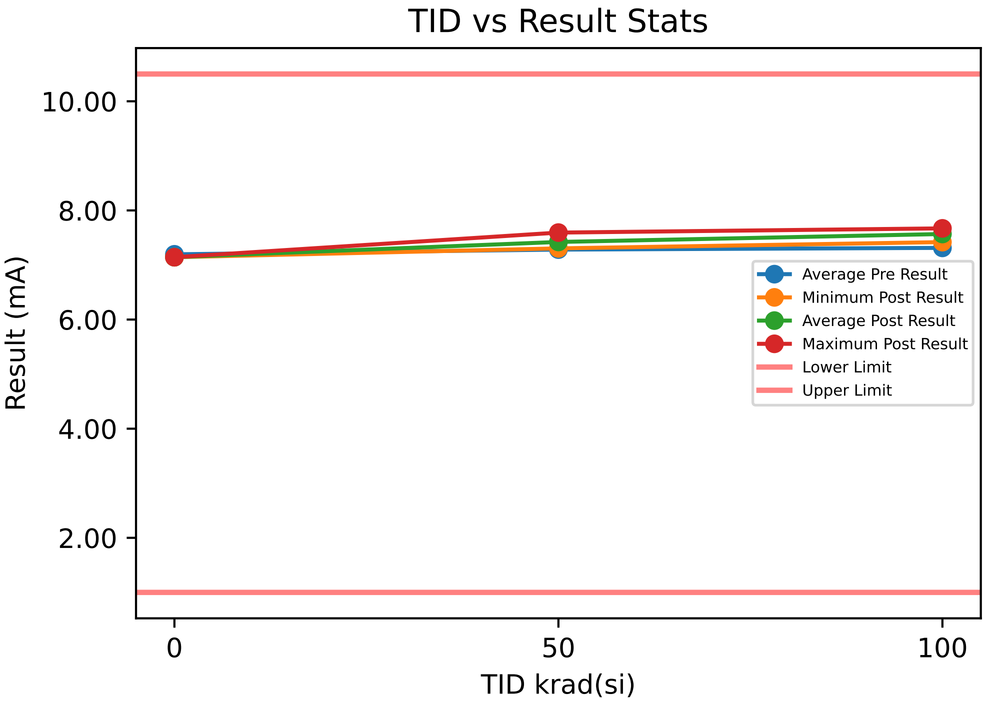
Test Results (Lower Limit = 1.0, Upper Limit = 17.0 (mA))

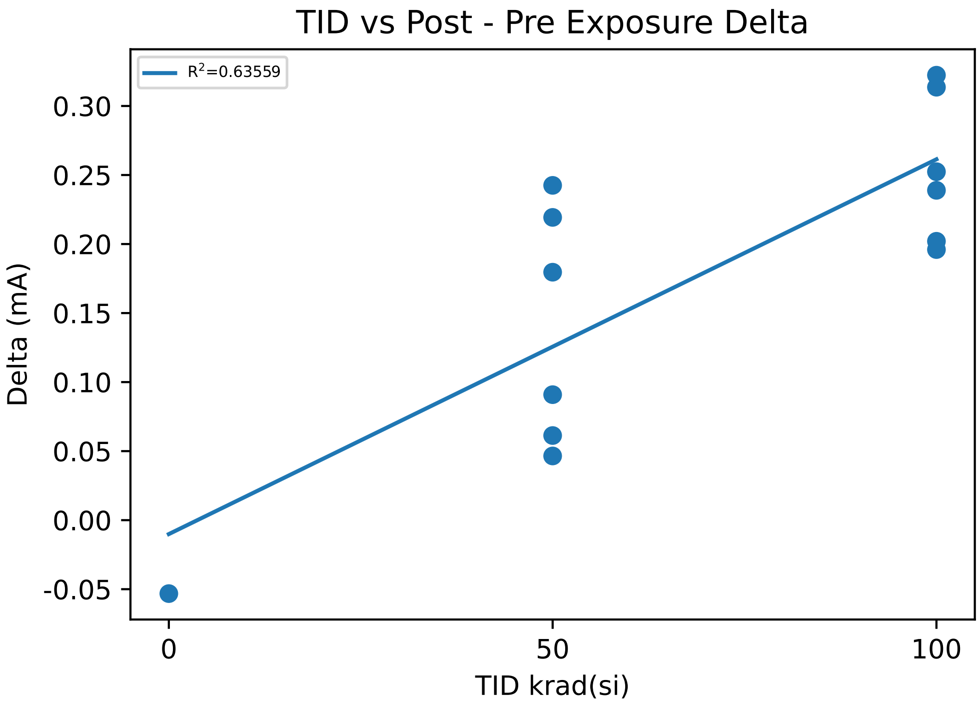
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	10.195	10.285	0.0905
60	50	Biased	10.06	10.398	0.3379
61	50	Biased	10.248	10.334	0.0863
63	100	Biased	10.271	10.568	0.2967
64	100	Biased	10.077	10.47	0.3932
65	100	Biased	10.211	10.558	0.3469
66	50	Unbiased	10.178	10.469	0.2908
67	50	Unbiased	10.174	10.23	0.0556
68	50	Unbiased	10.265	10.628	0.3634
69	100	Unbiased	10.369	10.672	0.3028
70	100	Unbiased	10.244	10.777	0.5325
71	100	Unbiased	10.254	10.441	0.1877
72	0	Control	9.9709	10.088	0.1166

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.9709	9.9709	9.9709		10.088	10.088	10.088		0.1166	0.1166	0.1166	
50	10.06	10.187	10.265	0.072308	10.23	10.391	10.628	0.14325	0.0556	0.20408	0.3634	0.14116
100	10.077	10.237	10.369	0.095193	10.441	10.581	10.777	0.12581	0.1877	0.3433	0.5325	0.11517

Device Test: 37.19 Iop HS BOOT IIM Interlock 2MHz VIN_14V





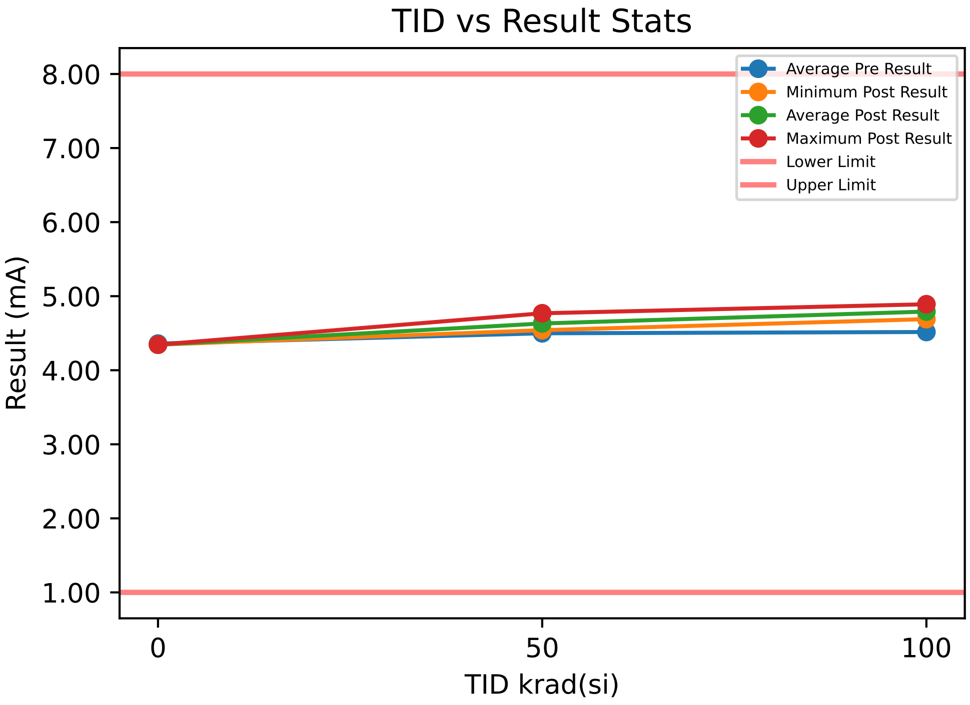
Test Results (Lower Limit = 1.0, Upper Limit = 10.5 (mA))

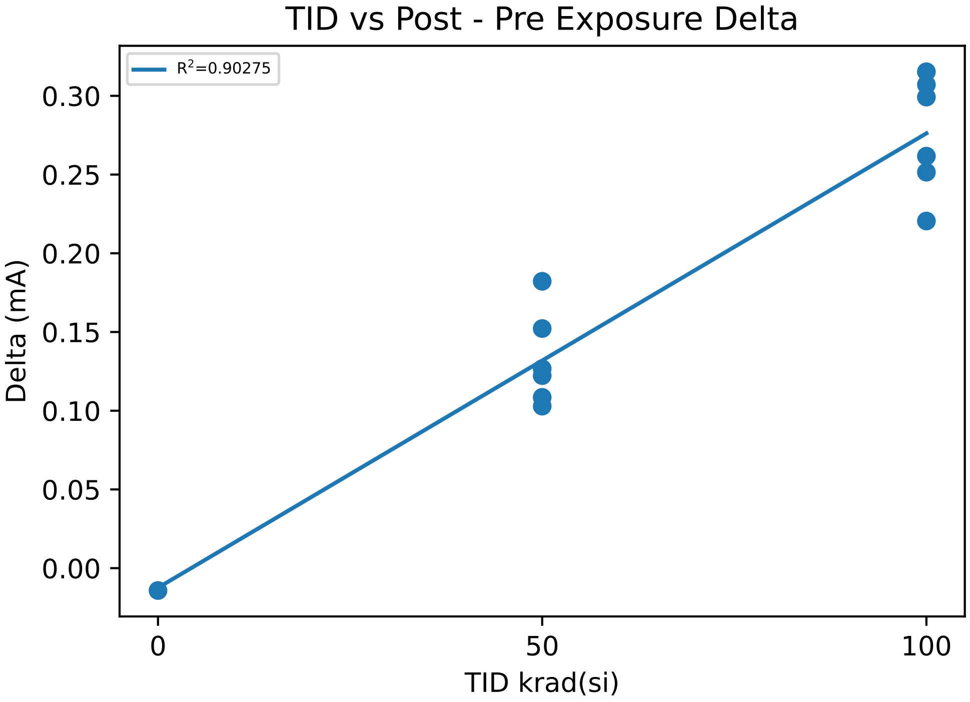
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.1249	7.3045	0.1796
60	50	Biased	7.2845	7.3754	0.0909
61	50	Biased	7.1203	7.3628	0.2425
63	100	Biased	7.285	7.5986	0.3136
64	100	Biased	7.2174	7.4194	0.202
65	100	Biased	7.4198	7.6587	0.2389
66	50	Unbiased	7.4754	7.5219	0.0465
67	50	Unbiased	7.3744	7.5937	0.2193
68	50	Unbiased	7.3125	7.3738	0.0613
69	100	Unbiased	7.2687	7.5211	0.2524
70	100	Unbiased	7.3414	7.5374	0.196
71	100	Unbiased	7.3487	7.671	0.3223
72	0	Control	7.1957	7.1425	-0.0532

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1957	7.1957	7.1957		7.1425	7.1425	7.1425		-0.0532	-0.0532	-0.0532	
50	7.1203	7.282	7.4754	0.13979	7.3045	7.422	7.5937	0.11069	0.0465	0.14002	0.2425	0.08451
100	7.2174	7.3135	7.4198	0.071234	7.4194	7.5677	7.671	0.094857	0.196	0.2542	0.3223	0.05388

Device Test: 37.2 Iq LS VIN IIM Interlock VIN_14V





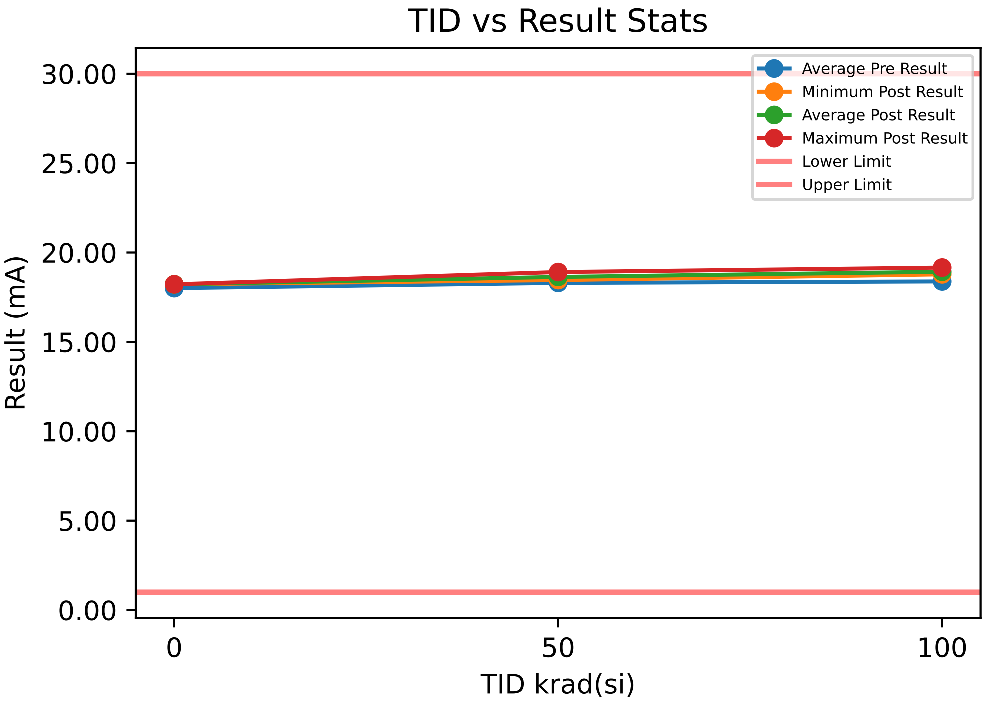
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

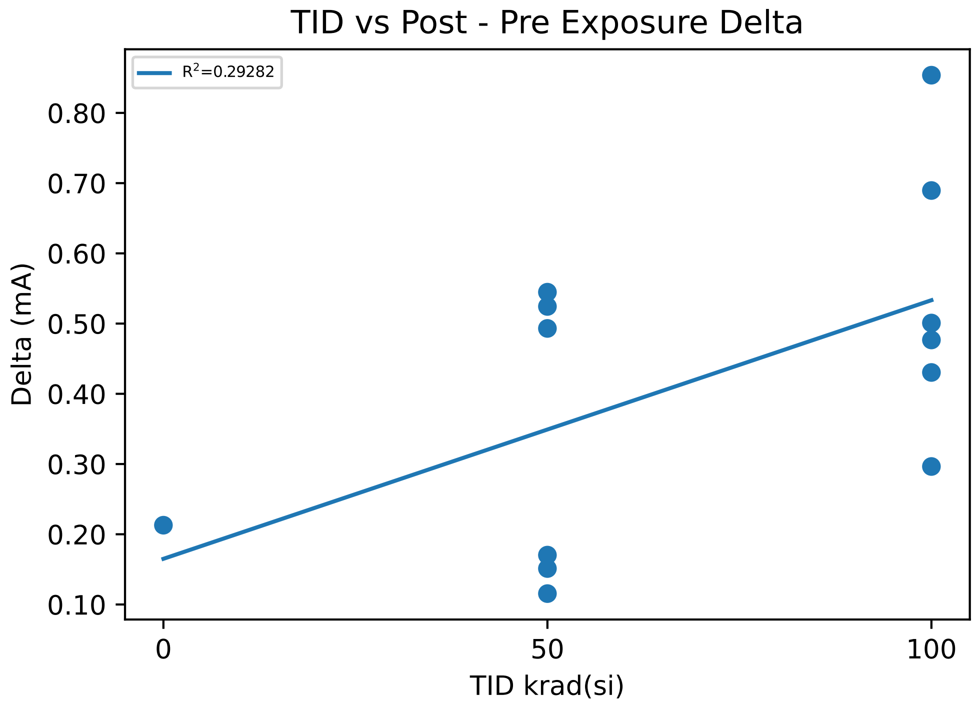
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.4691	4.5958	0.1267
60	50	Biased	4.4702	4.6224	0.1522
61	50	Biased	4.5197	4.642	0.1223
63	100	Biased	4.5199	4.8352	0.3153
64	100	Biased	4.474	4.7357	0.2617
65	100	Biased	4.4604	4.7119	0.2515
66	50	Unbiased	4.5081	4.6166	0.1085
67	50	Unbiased	4.4379	4.5408	0.1029
68	50	Unbiased	4.5869	4.7691	0.1822
69	100	Unbiased	4.5838	4.8909	0.3071
70	100	Unbiased	4.5897	4.8889	0.2992
71	100	Unbiased	4.4693	4.6898	0.2205
72	0	Control	4.3593	4.3451	-0.0142

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3593	4.3593	4.3593		4.3451	4.3451	4.3451		-0.0142	-0.0142	-0.0142	
50	4.4379	4.4987	4.5869	0.052333	4.5408	4.6311	4.7691	0.075959	0.1029	0.13247	0.1822	0.029826
100	4.4604	4.5162	4.5897	0.058446	4.6898	4.7921	4.8909	0.090628	0.2205	0.27588	0.3153	0.037242

Device Test: 37.20 Iop LS VIN IIM Interlock 5MHz VIN_14V





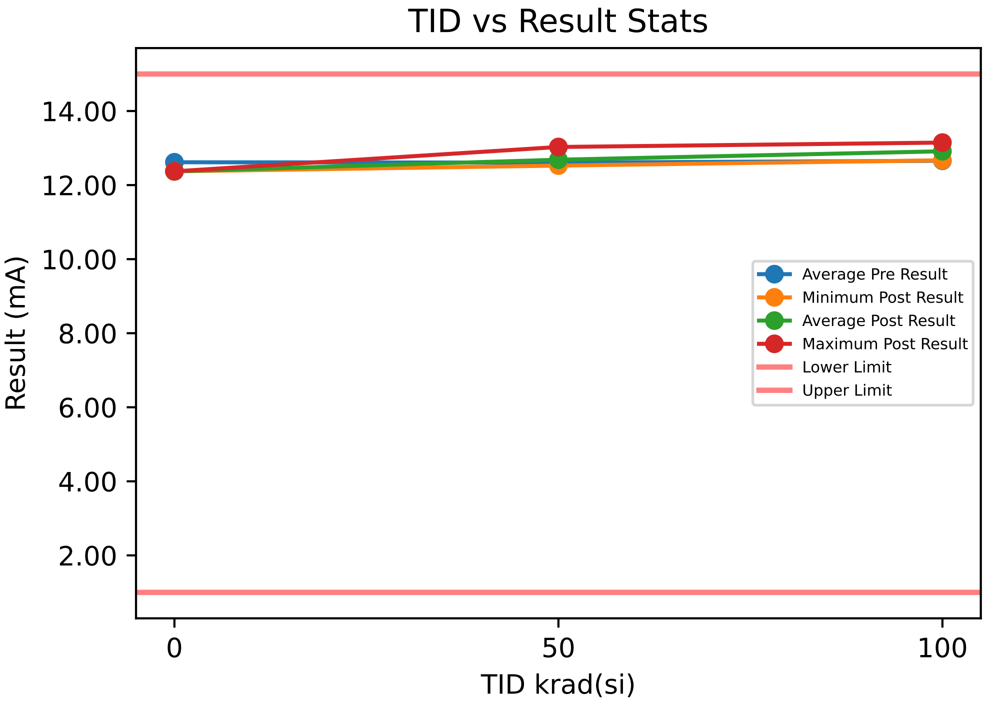
Test Results (Lower Limit = 1.0, Upper Limit = 30.0 (mA))

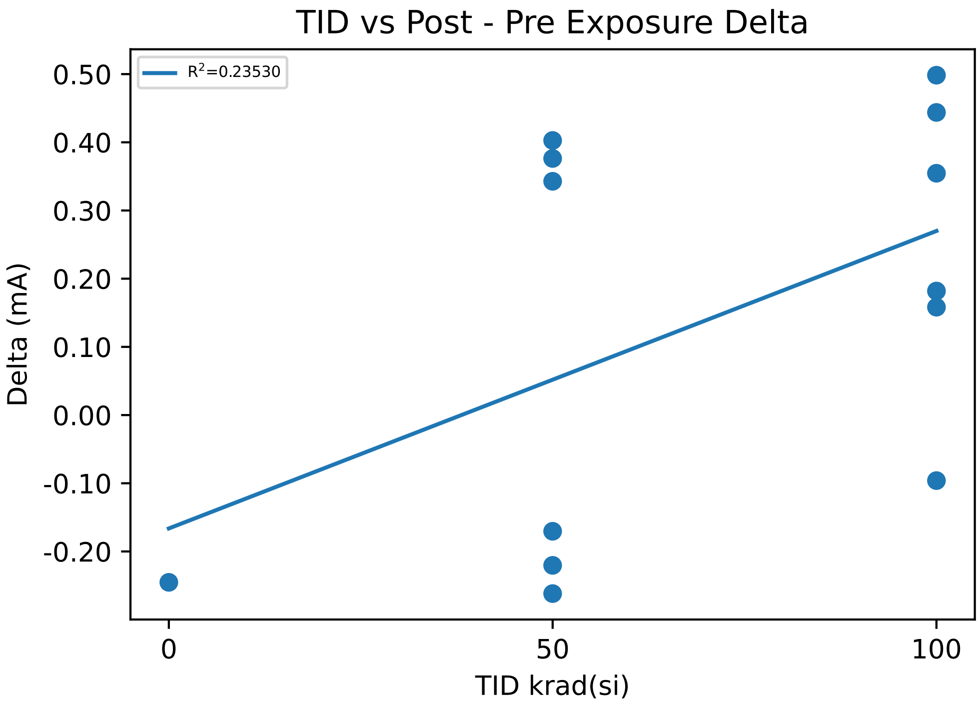
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	18.365	18.535	0.1703
60	50	Biased	18.085	18.61	0.5244
61	50	Biased	18.409	18.56	0.1512
63	100	Biased	18.431	18.862	0.4304
64	100	Biased	18.108	18.798	0.6895
65	100	Biased	18.397	18.873	0.4767
66	50	Unbiased	18.236	18.729	0.4931
67	50	Unbiased	18.343	18.459	0.1155
68	50	Unbiased	18.363	18.908	0.5447
69	100	Unbiased	18.576	19.076	0.5008
70	100	Unbiased	18.304	19.157	0.8537
71	100	Unbiased	18.483	18.779	0.2965
72	0	Control	18.009	18.221	0.2129

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.009	18.009	18.009		18.221	18.221	18.221		0.2129	0.2129	0.2129	
50	18.085	18.3	18.409	0.12005	18.459	18.633	18.908	0.16162	0.1155	0.3332	0.5447	0.20684
100	18.108	18.383	18.576	0.16201	18.779	18.924	19.157	0.15566	0.2965	0.54127	0.8537	0.19879

Device Test: 37.21 Iop HS BOOT IIM Interlock 5MHz VIN_14V





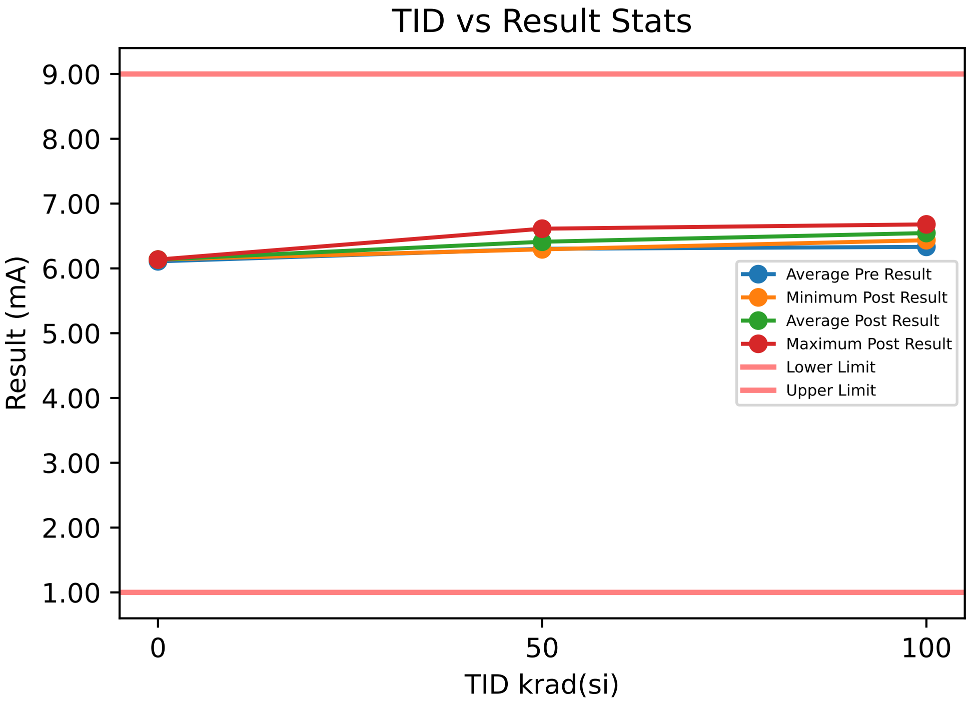
Test Results (Lower Limit = 1.0, Upper Limit = 15.0 (mA))

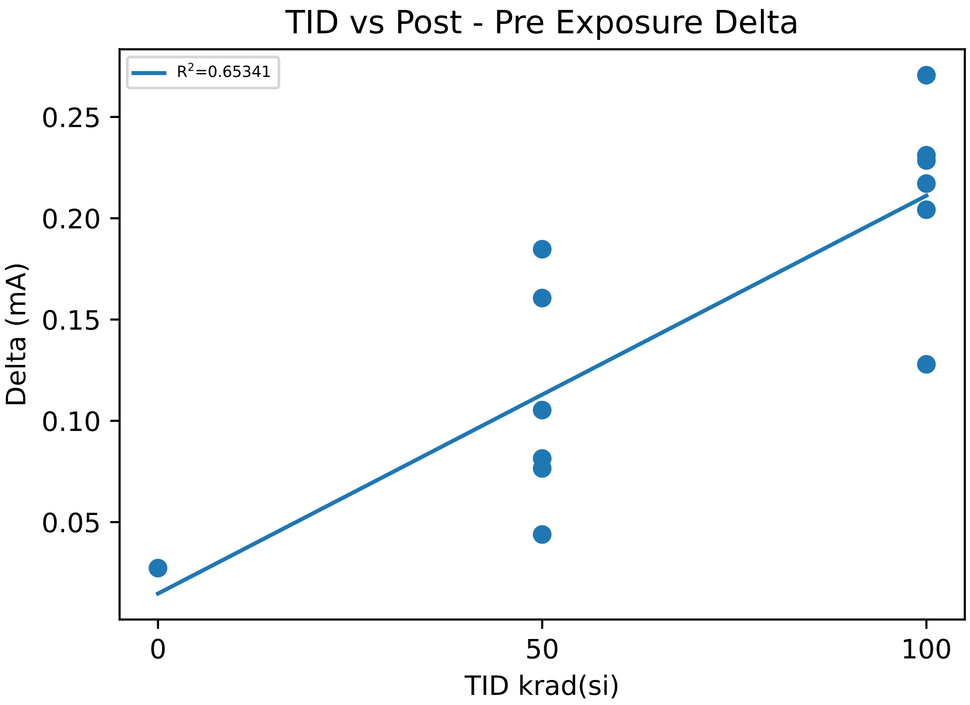
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	12.342	12.685	0.3428
60	50	Biased	12.7	12.529	-0.1704
61	50	Biased	12.325	12.727	0.4027
63	100	Biased	12.576	13.02	0.4438
64	100	Biased	12.659	12.841	0.1819
65	100	Biased	12.757	12.915	0.1582
66	50	Unbiased	12.875	12.614	-0.2618
67	50	Unbiased	12.653	13.029	0.3763
68	50	Unbiased	12.747	12.526	-0.2204
69	100	Unbiased	12.531	12.886	0.3546
70	100	Unbiased	12.766	12.67	-0.0961
71	100	Unbiased	12.649	13.148	0.4984
72	0	Control	12.617	12.371	-0.2453

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.617	12.617	12.617		12.371	12.371	12.371		-0.2453	-0.2453	-0.2453	
50	12.325	12.607	12.875	0.22442	12.526	12.685	13.029	0.18696	-0.2618	0.0782	0.4027	0.3258
100	12.531	12.656	12.766	0.094292	12.67	12.913	13.148	0.1622	-0.0961	0.2568	0.4984	0.22035

Device Test: 37.22 Iop LS VIN IIM Interlock Disable 500kHz VIN_14V





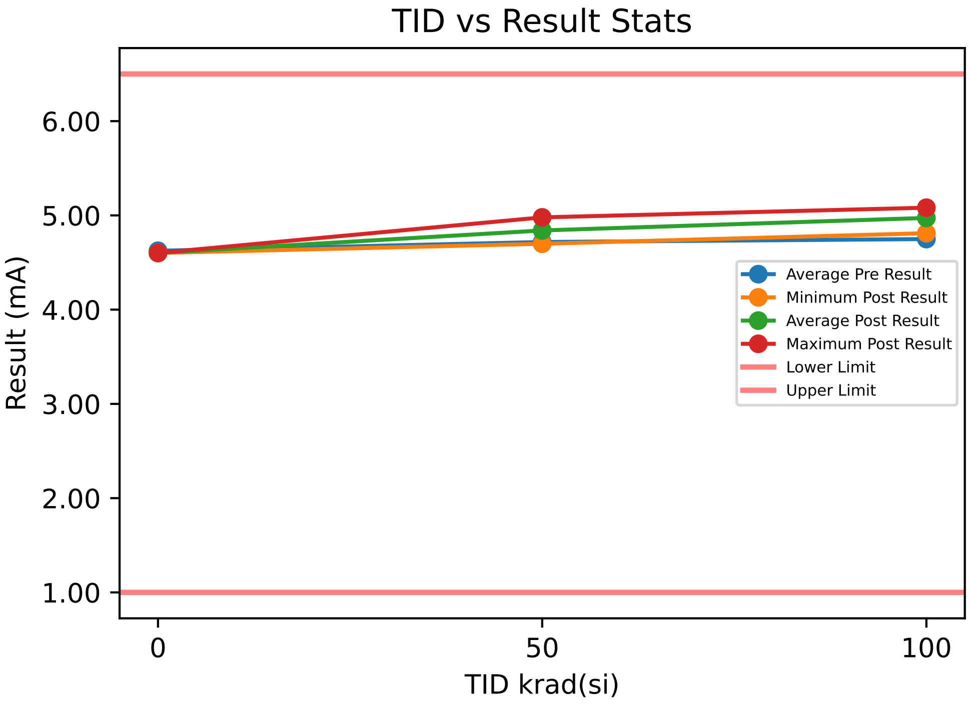
Test Results (Lower Limit = 1.0, Upper Limit = 9.0 (mA))

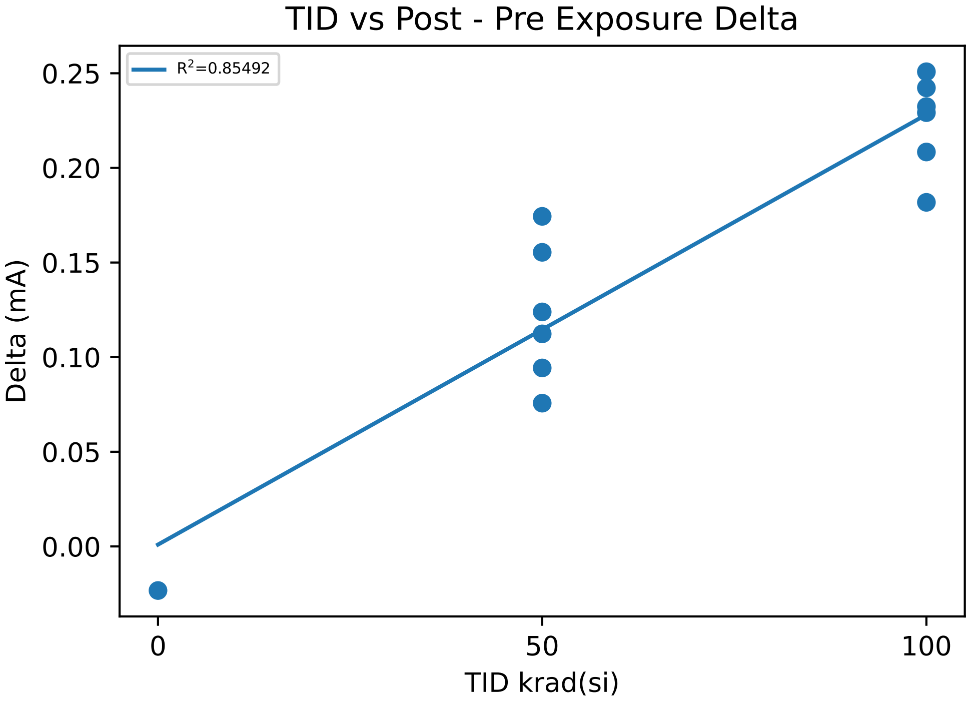
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.2419	6.3233	0.0814
60	50	Biased	6.2061	6.3667	0.1606
61	50	Biased	6.3159	6.3924	0.0765
63	100	Biased	6.3664	6.5949	0.2285
64	100	Biased	6.2193	6.4504	0.2311
65	100	Biased	6.2792	6.4834	0.2042
66	50	Unbiased	6.373	6.4783	0.1053
67	50	Unbiased	6.2498	6.2937	0.0439
68	50	Unbiased	6.428	6.6127	0.1847
69	100	Unbiased	6.414	6.6311	0.2171
70	100	Unbiased	6.4086	6.6792	0.2706
71	100	Unbiased	6.3069	6.4348	0.1279
72	0	Control	6.1089	6.1362	0.0273

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.1089	6.1089	6.1089		6.1362	6.1362	6.1362		0.0273	0.0273	0.0273	
50	6.2061	6.3025	6.428	0.085607	6.2937	6.4112	6.6127	0.11745	0.0439	0.10873	0.1847	0.053782
100	6.2193	6.3324	6.414	0.077322	6.4348	6.5456	6.6792	0.10276	0.1279	0.21323	0.2706	0.047374

Device Test: 37.23 Iop HS BOOT IIM Interlock Disable 500kHz VIN_14V





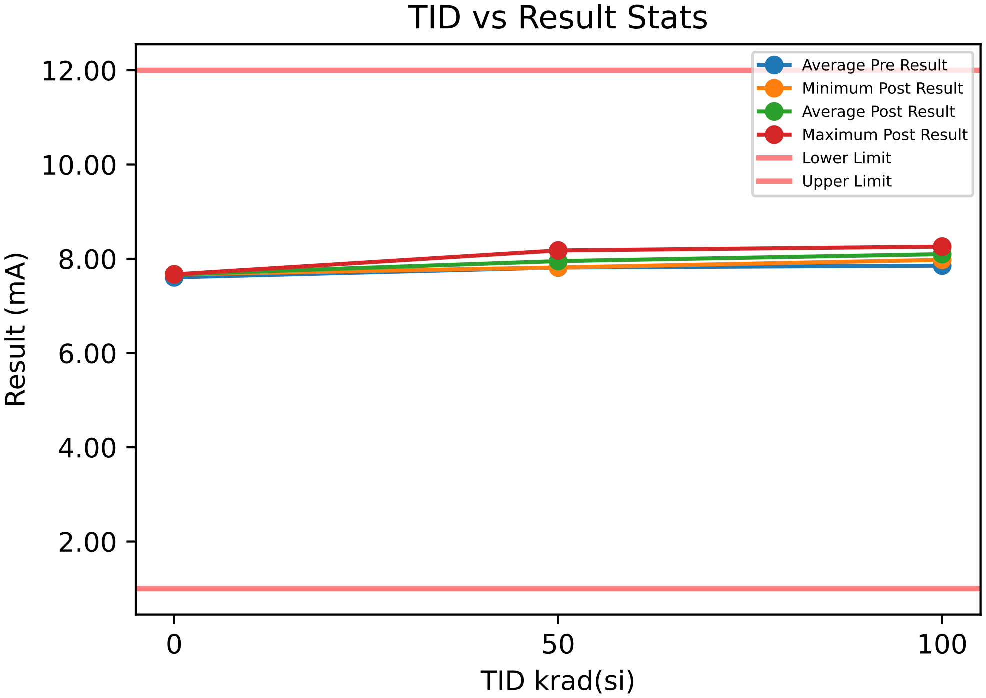
Test Results (Lower Limit = 1.0, Upper Limit = 6.5 (mA))

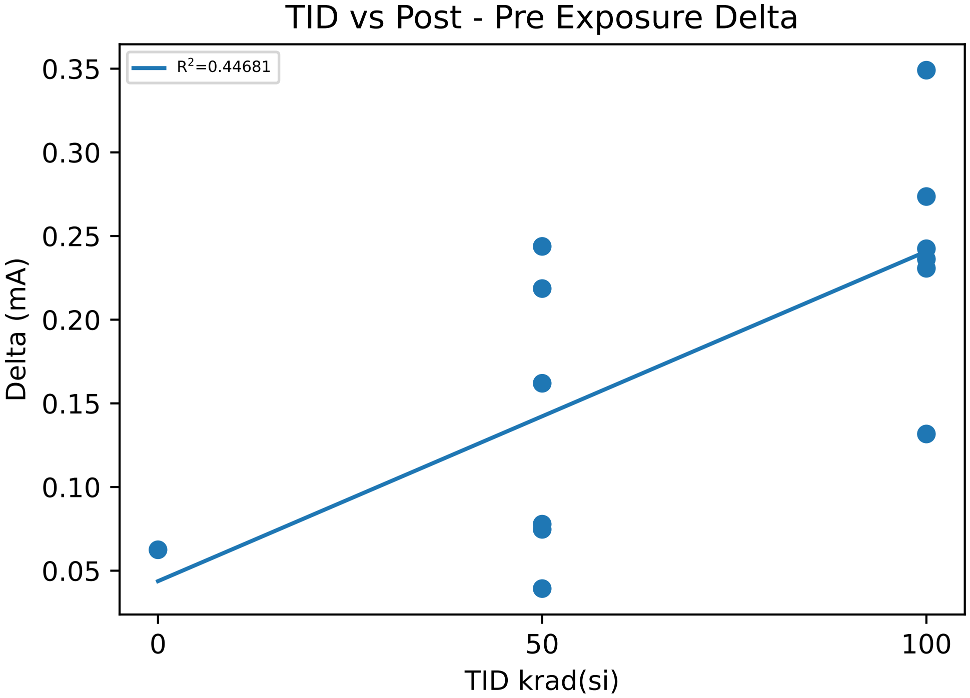
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.5864	4.6987	0.1123
60	50	Biased	4.7089	4.8328	0.1239
61	50	Biased	4.5742	4.7486	0.1744
63	100	Biased	4.7318	4.9826	0.2508
64	100	Biased	4.6292	4.811	0.1818
65	100	Biased	4.8523	5.0815	0.2292
66	50	Unbiased	4.8948	4.9705	0.0757
67	50	Unbiased	4.8234	4.9788	0.1554
68	50	Unbiased	4.7169	4.8112	0.0943
69	100	Unbiased	4.7148	4.9232	0.2084
70	100	Unbiased	4.7669	4.9993	0.2324
71	100	Unbiased	4.7973	5.0396	0.2423
72	0	Control	4.6245	4.6012	-0.0233

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6245	4.6245	4.6245		4.6012	4.6012	4.6012		-0.0233	-0.0233	-0.0233	
50	4.5742	4.7174	4.8948	0.12684	4.6987	4.8401	4.9788	0.11445	0.0757	0.12267	0.1744	0.03706
100	4.6292	4.7487	4.8523	0.076343	4.811	4.9729	5.0815	0.09562	0.1818	0.22415	0.2508	0.025198

Device Test: 37.24 Iop LS VIN IIM Interlock Disable 1MHz VIN_14V





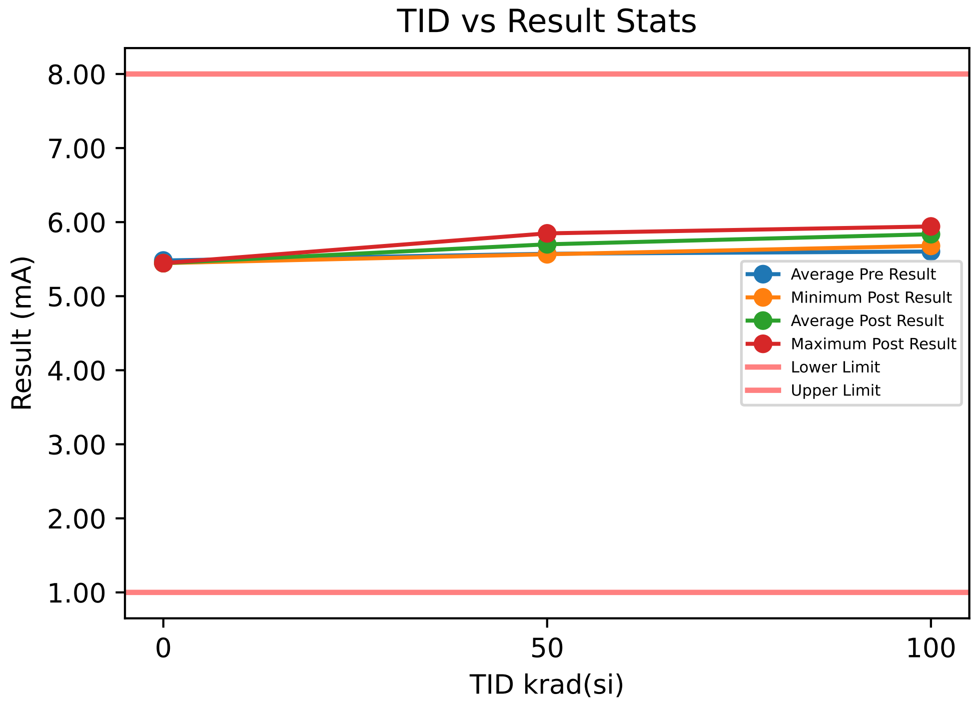
Test Results (Lower Limit = 1.0, Upper Limit = 12.0 (mA))

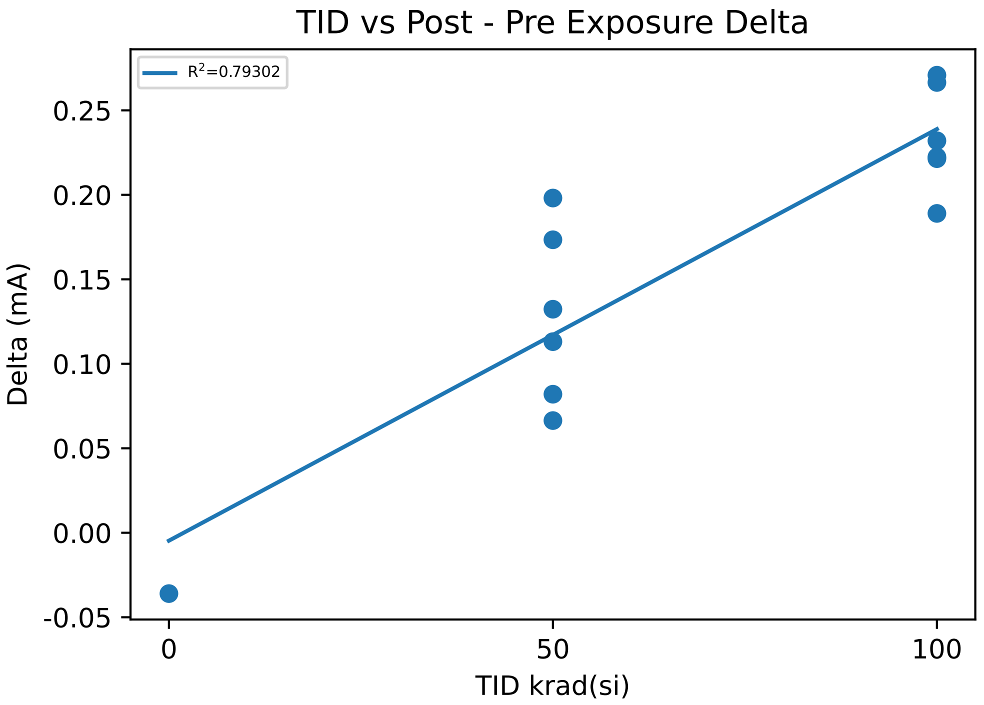
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.7688	7.8466	0.0778
60	50	Biased	7.6984	7.917	0.2186
61	50	Biased	7.8406	7.9153	0.0747
63	100	Biased	7.892	8.1282	0.2362
64	100	Biased	7.715	7.9886	0.2736
65	100	Biased	7.8095	8.0519	0.2424
66	50	Unbiased	7.8715	8.0335	0.162
67	50	Unbiased	7.7763	7.8156	0.0393
68	50	Unbiased	7.9329	8.1767	0.2438
69	100	Unbiased	7.9535	8.1842	0.2307
70	100	Unbiased	7.9093	8.2584	0.3491
71	100	Unbiased	7.846	7.9777	0.1317
72	0	Control	7.6063	7.6688	0.0625

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.6063	7.6063	7.6063		7.6688	7.6688	7.6688		0.0625	0.0625	0.0625	
50	7.6984	7.8148	7.9329	0.083637	7.8156	7.9508	8.1767	0.13372	0.0393	0.13603	0.2438	0.084398
100	7.715	7.8542	7.9535	0.084578	7.9777	8.0982	8.2584	0.11193	0.1317	0.24395	0.3491	0.07039

Device Test: 37.25 Iop HS BOOT IIM Interlock Disable 1MHz VIN_14V





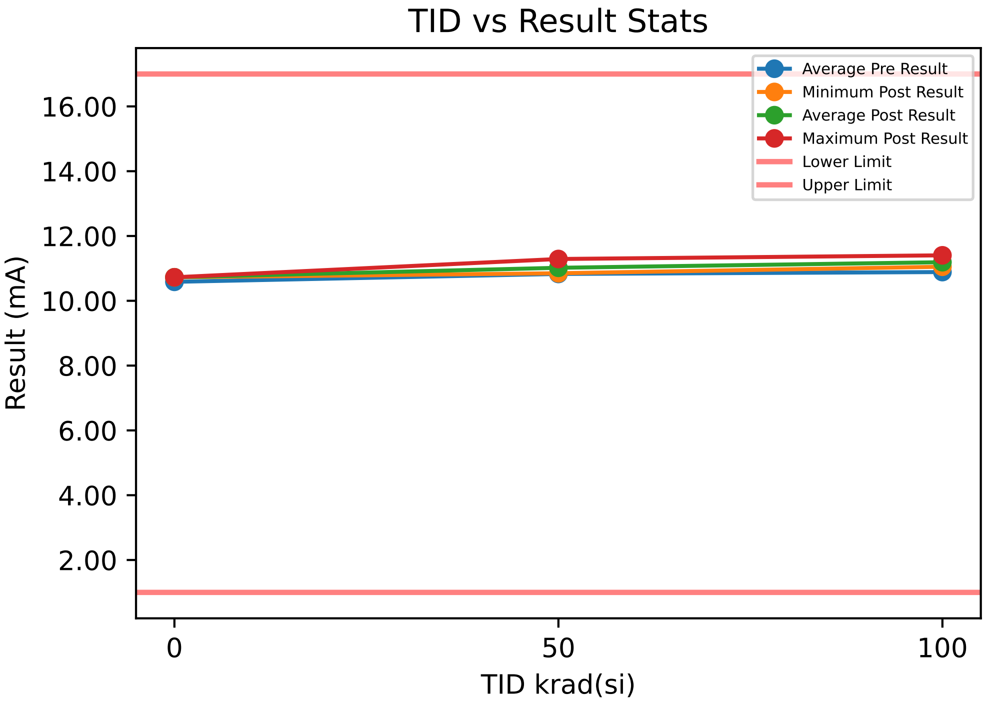
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

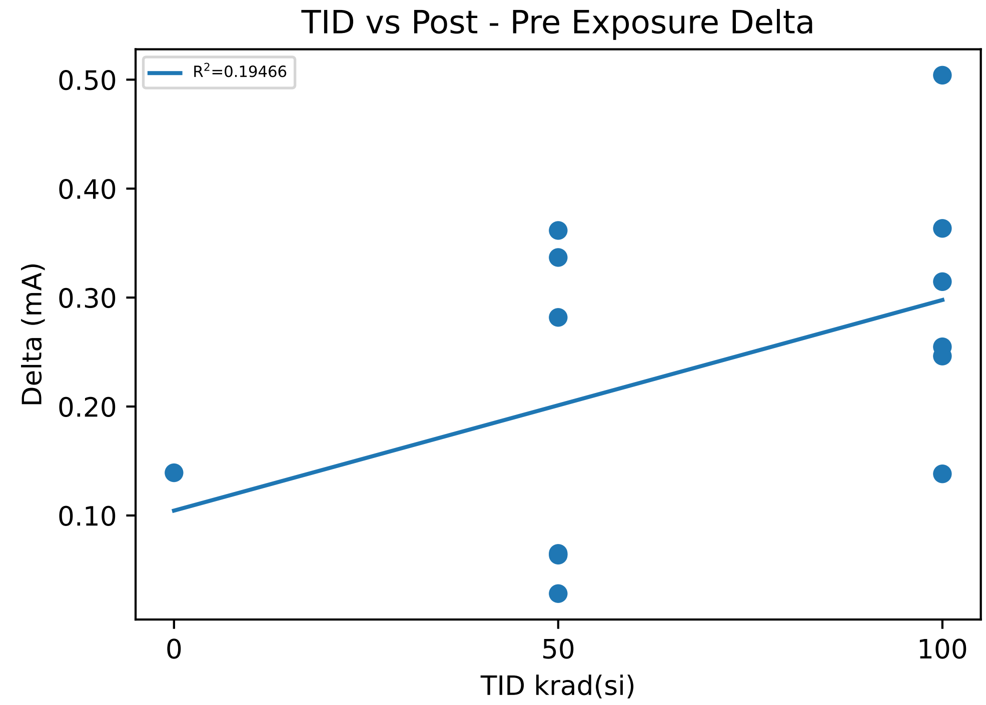
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.4333	5.5656	0.1323
60	50	Biased	5.5679	5.681	0.1131
61	50	Biased	5.4231	5.6212	0.1981
63	100	Biased	5.5822	5.853	0.2708
64	100	Biased	5.4901	5.6791	0.189
65	100	Biased	5.7094	5.9414	0.232
66	50	Unbiased	5.754	5.8204	0.0664
67	50	Unbiased	5.6746	5.848	0.1734
68	50	Unbiased	5.582	5.664	0.082
69	100	Unbiased	5.5649	5.7873	0.2224
70	100	Unbiased	5.6239	5.8453	0.2214
71	100	Unbiased	5.6479	5.9144	0.2665
72	0	Control	5.4819	5.4459	-0.036

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4819	5.4819	5.4819		5.4459	5.4459	5.4459		-0.036	-0.036	-0.036	
50	5.4231	5.5725	5.754	0.13052	5.5656	5.7	5.848	0.11165	0.0664	0.12755	0.1981	0.051235
100	5.4901	5.6031	5.7094	0.075372	5.6791	5.8367	5.9414	0.094464	0.189	0.23368	0.2708	0.030764

Device Test: 37.26 Iop LS VIN IIM Interlock Disable 2MHz VIN_14V





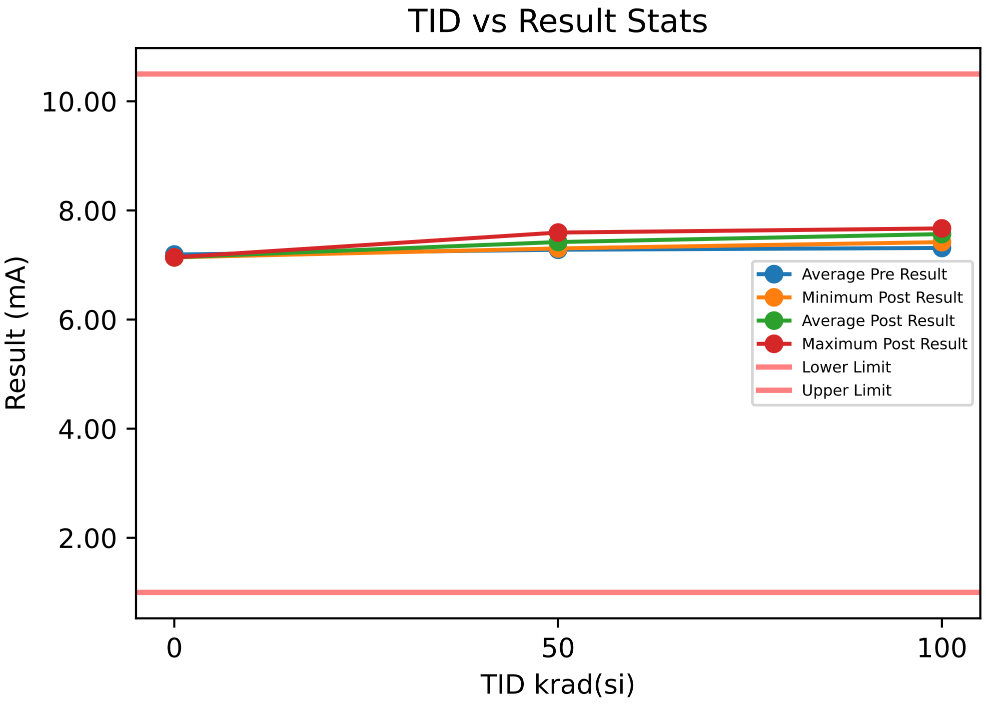
Test Results (Lower Limit = 1.0, Upper Limit = 17.0 (mA))

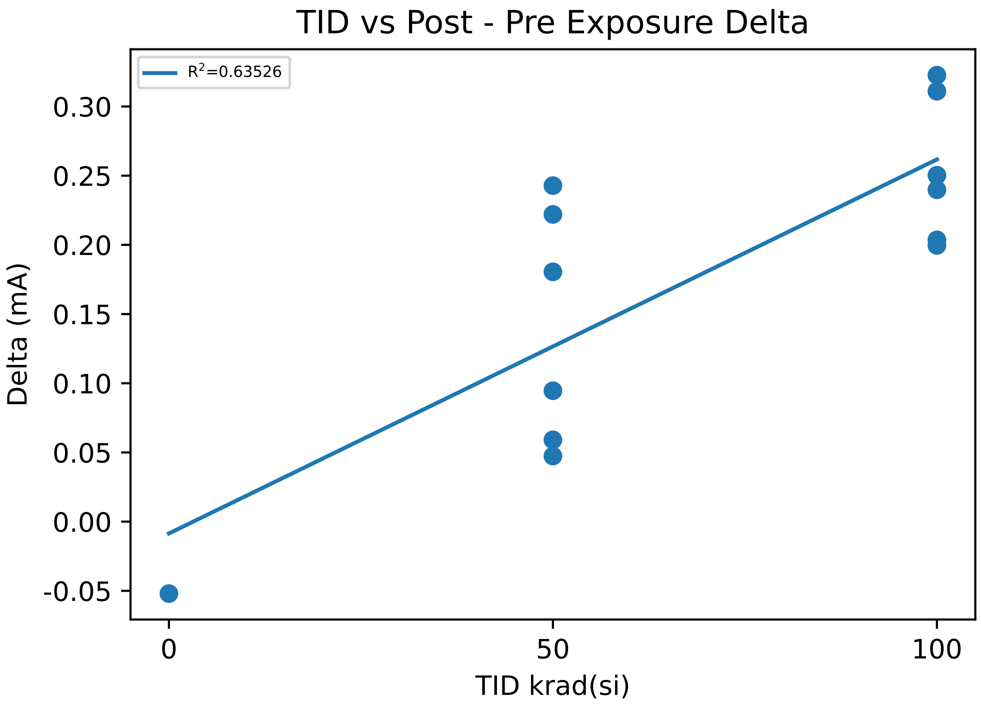
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	10.818	10.883	0.0652
60	50	Biased	10.668	11.005	0.3368
61	50	Biased	10.881	10.945	0.0636
63	100	Biased	10.934	11.181	0.2463
64	100	Biased	10.691	11.054	0.3635
65	100	Biased	10.863	11.177	0.3146
66	50	Unbiased	10.856	11.138	0.2818
67	50	Unbiased	10.822	10.85	0.0283
68	50	Unbiased	10.929	11.29	0.3616
69	100	Unbiased	11.024	11.278	0.2548
70	100	Unbiased	10.899	11.403	0.5041
71	100	Unbiased	10.913	11.052	0.1382
72	0	Control	10.586	10.725	0.1392

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.586	10.586	10.586		10.725	10.725	10.725		0.1392	0.1392	0.1392	
50	10.668	10.829	10.929	0.08866	10.85	11.019	11.29	0.16756	0.0283	0.18955	0.3616	0.15305
100	10.691	10.887	11.024	0.11032	11.052	11.191	11.403	0.13502	0.1382	0.30358	0.5041	0.12404

Device Test: 37.27 Iop HS BOOT IIM Interlock Disable 2MHz VIN_14V





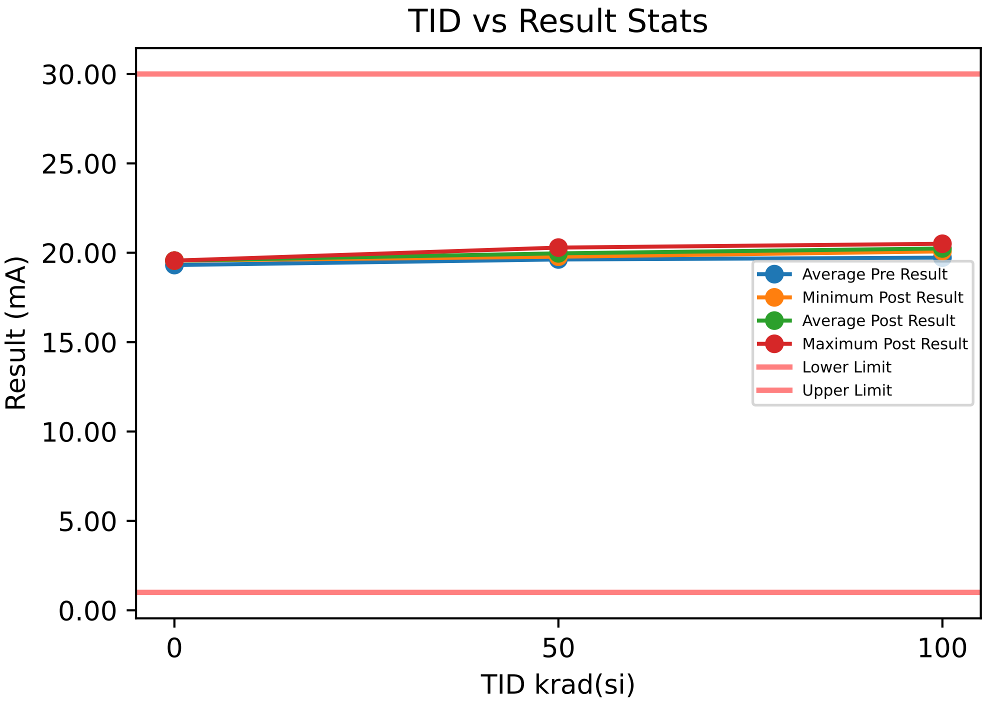
Test Results (Lower Limit = 1.0, Upper Limit = 10.5 (mA))

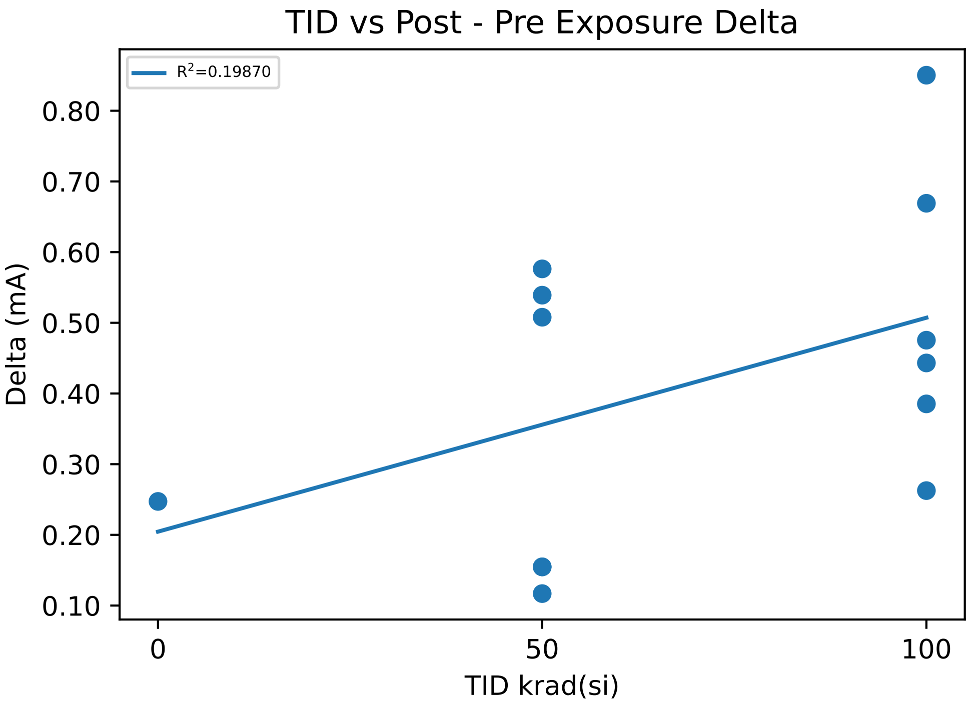
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.1233	7.3038	0.1805
60	50	Biased	7.2819	7.3765	0.0946
61	50	Biased	7.1174	7.3602	0.2428
63	100	Biased	7.2849	7.5959	0.311
64	100	Biased	7.2154	7.419	0.2036
65	100	Biased	7.4186	7.6584	0.2398
66	50	Unbiased	7.4719	7.5193	0.0474
67	50	Unbiased	7.3724	7.5944	0.222
68	50	Unbiased	7.3102	7.3693	0.0591
69	100	Unbiased	7.2674	7.5177	0.2503
70	100	Unbiased	7.339	7.5386	0.1996
71	100	Unbiased	7.3478	7.6704	0.3226
72	0	Control	7.1922	7.1402	-0.052

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1922	7.1922	7.1922		7.1402	7.1402	7.1402		-0.052	-0.052	-0.052	
50	7.1174	7.2795	7.4719	0.13948	7.3038	7.4206	7.5944	0.11119	0.0474	0.14107	0.2428	0.084978
100	7.2154	7.3122	7.4186	0.071315	7.419	7.5667	7.6704	0.094891	0.1996	0.25448	0.3226	0.052285

Device Test: 37.28 Iop LS VIN IIM Interlock Disable 5MHz VIN_14V





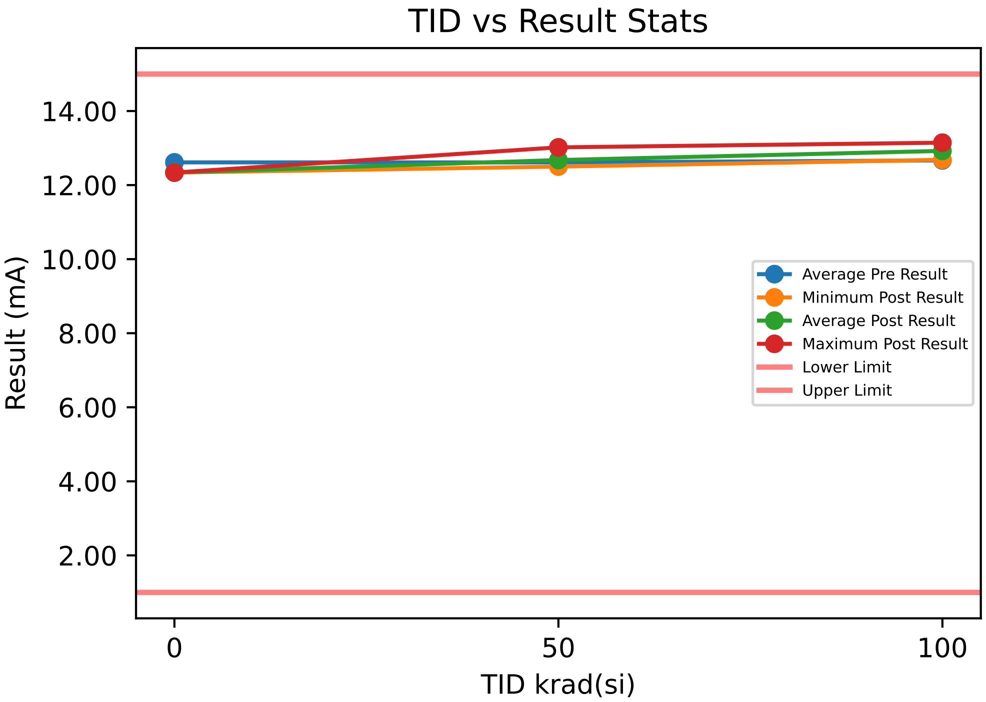
Test Results (Lower Limit = 1.0, Upper Limit = 30.0 (mA))

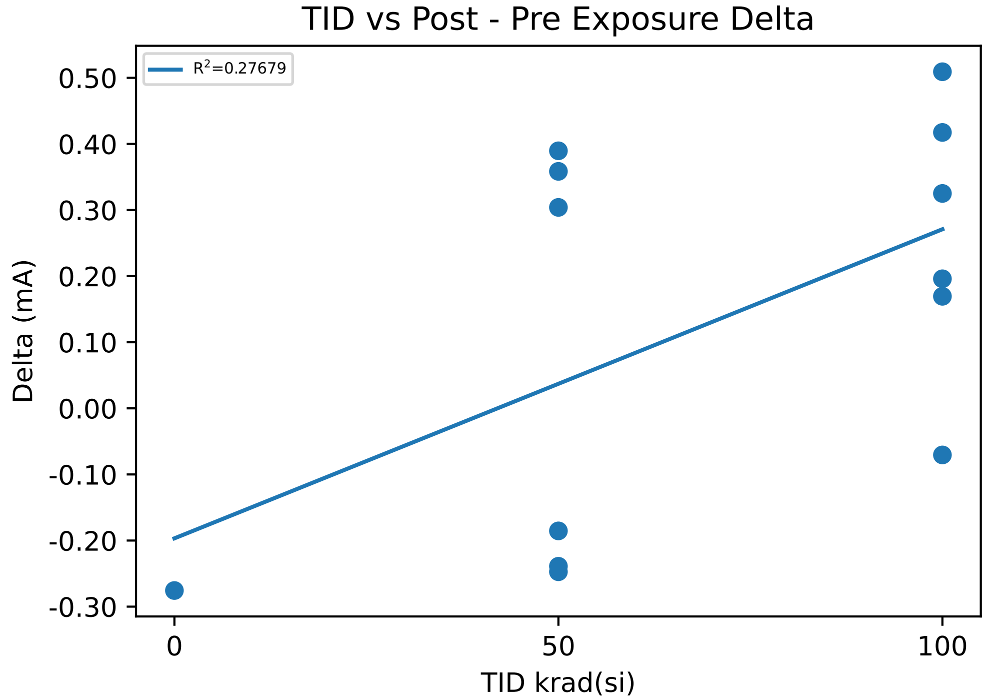
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	19.678	19.833	0.1547
60	50	Biased	19.38	19.919	0.5391
61	50	Biased	19.717	19.872	0.1547
63	100	Biased	19.788	20.173	0.3853
64	100	Biased	19.407	20.076	0.6691
65	100	Biased	19.733	20.209	0.4754
66	50	Unbiased	19.602	20.11	0.5079
67	50	Unbiased	19.661	19.778	0.1169
68	50	Unbiased	19.712	20.288	0.5763
69	100	Unbiased	19.946	20.39	0.4432
70	100	Unbiased	19.653	20.503	0.8503
71	100	Unbiased	19.829	20.091	0.2626
72	0	Control	19.312	19.559	0.2473

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.312	19.312	19.312		19.559	19.559	19.559		0.2473	0.2473	0.2473	
50	19.38	19.625	19.717	0.12718	19.778	19.967	20.288	0.19426	0.1169	0.3416	0.5763	0.22005
100	19.407	19.726	19.946	0.18443	20.076	20.24	20.503	0.17077	0.2626	0.51432	0.8503	0.21139

Device Test: 37.29 Iop HS BOOT IIM Interlock Disable 5MHz VIN_14V





Test Results (Lower Limit = 1.0, Upper Limit = 15.0 (mA))

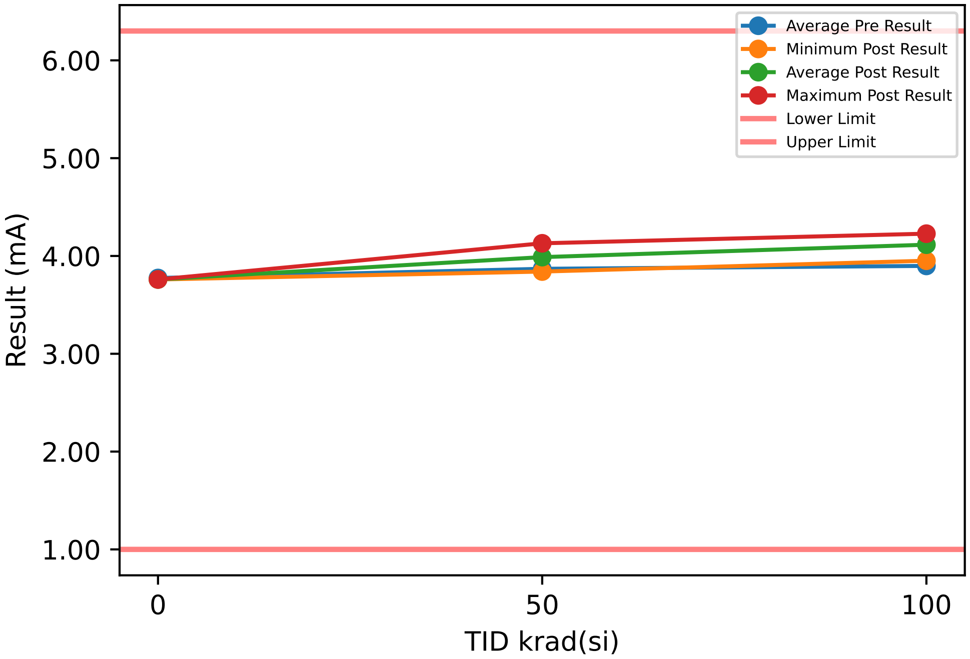
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	12.375	12.679	0.304
60	50	Biased	12.693	12.507	-0.1854
61	50	Biased	12.331	12.721	0.3896
63	100	Biased	12.608	13.026	0.4174
64	100	Biased	12.653	12.849	0.196
65	100	Biased	12.776	12.946	0.1695
66	50	Unbiased	12.868	12.629	-0.2389
67	50	Unbiased	12.661	13.019	0.3585
68	50	Unbiased	12.747	12.5	-0.2472
69	100	Unbiased	12.567	12.892	0.3251
70	100	Unbiased	12.754	12.684	-0.0705
71	100	Unbiased	12.636	13.145	0.5092
72	0	Control	12.614	12.338	-0.2756

Test Statistics (mA)

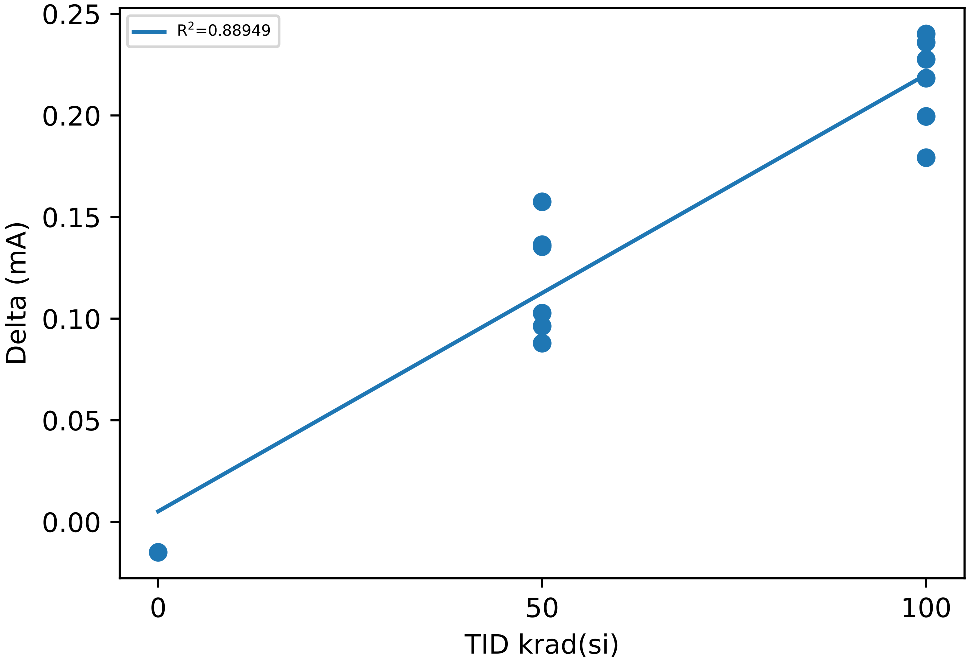
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.614	12.614	12.614		12.338	12.338	12.338		-0.2756	-0.2756	-0.2756	
50	12.331	12.613	12.868	0.21326	12.5	12.676	13.019	0.19039	-0.2472	0.063433	0.3896	0.31659
100	12.567	12.666	12.776	0.082742	12.684	12.924	13.145	0.15756	-0.0705	0.25778	0.5092	0.2062

Device Test: 37.3 Iq HS BOOT IIM Interlock VIN_14V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



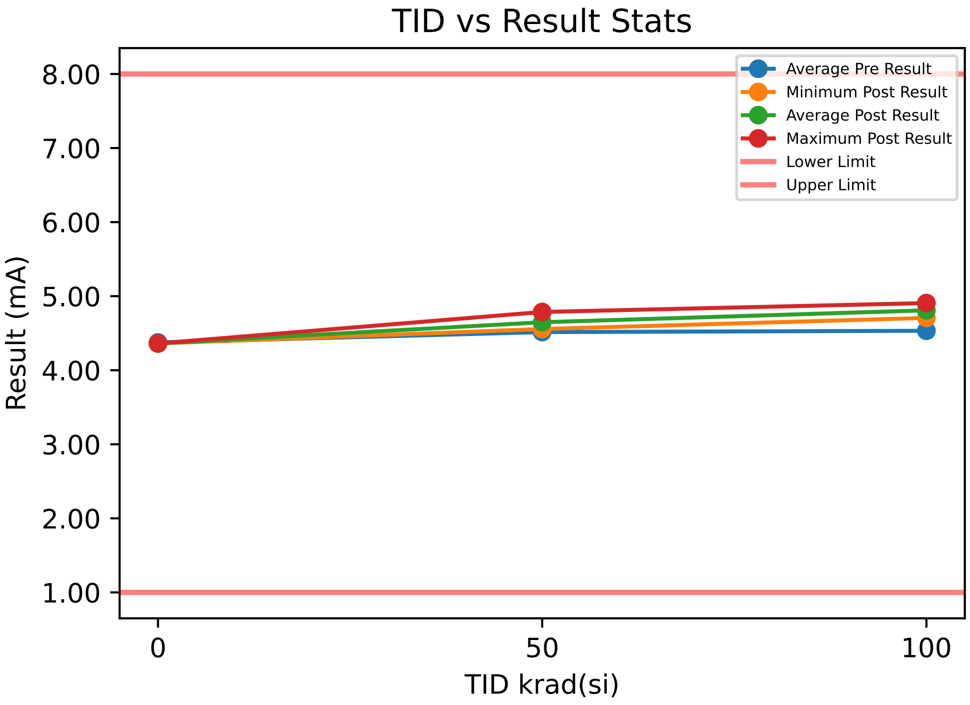
Test Results (Lower Limit = 1.0, Upper Limit = 6.3 (mA))

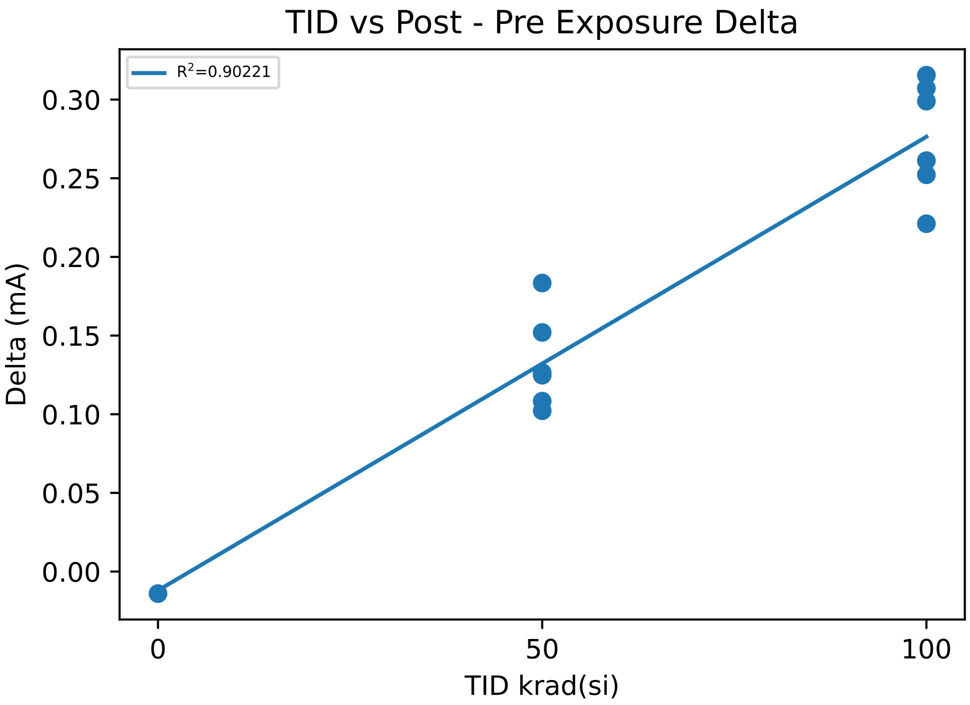
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.7442	3.8405	0.0963
60	50	Biased	3.8582	3.9936	0.1354
61	50	Biased	3.7316	3.8891	0.1575
63	100	Biased	3.8842	4.1201	0.2359
64	100	Biased	3.7721	3.9513	0.1792
65	100	Biased	4.0003	4.2279	0.2276
66	50	Unbiased	4.0416	4.1295	0.0879
67	50	Unbiased	3.9769	4.1133	0.1364
68	50	Unbiased	3.8601	3.9628	0.1027
69	100	Unbiased	3.8667	4.0662	0.1995
70	100	Unbiased	3.915	4.1551	0.2401
71	100	Unbiased	3.9514	4.1697	0.2183
72	0	Control	3.7747	3.7597	-0.015

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7747	3.7747	3.7747		3.7597	3.7597	3.7597		-0.015	-0.015	-0.015	
50	3.7316	3.8688	4.0416	0.12336	3.8405	3.9881	4.1295	0.11656	0.0879	0.11937	0.1575	0.027573
100	3.7721	3.8983	4.0003	0.078264	3.9513	4.1151	4.2279	0.09649	0.1792	0.21677	0.2401	0.023408

Device Test: 37.4 Iq LS VIN IIM Interlock Disable VIN_14V





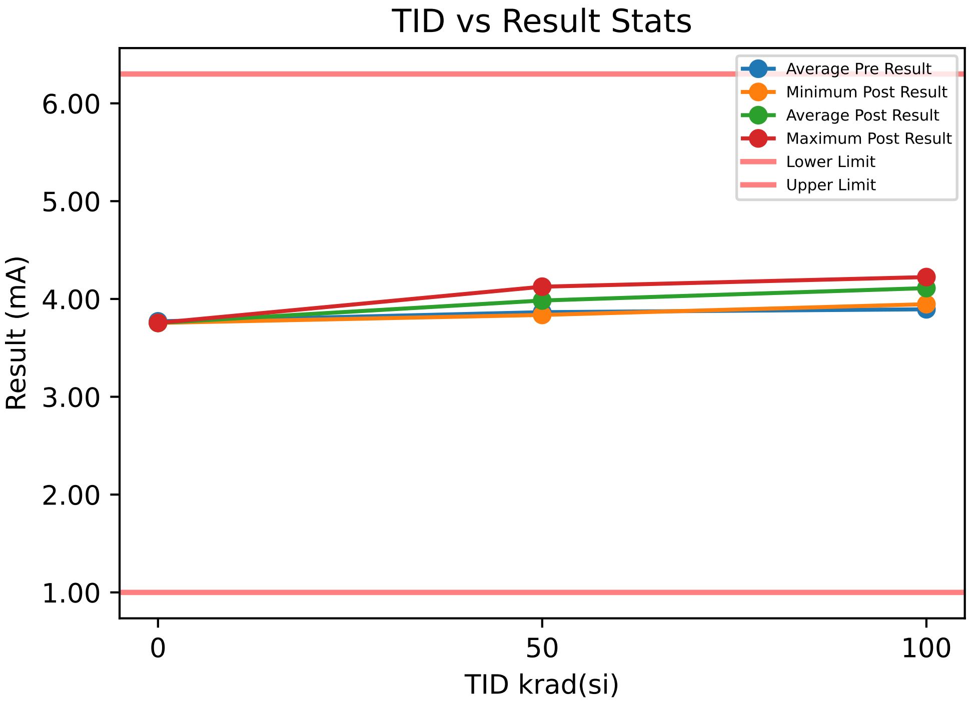
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

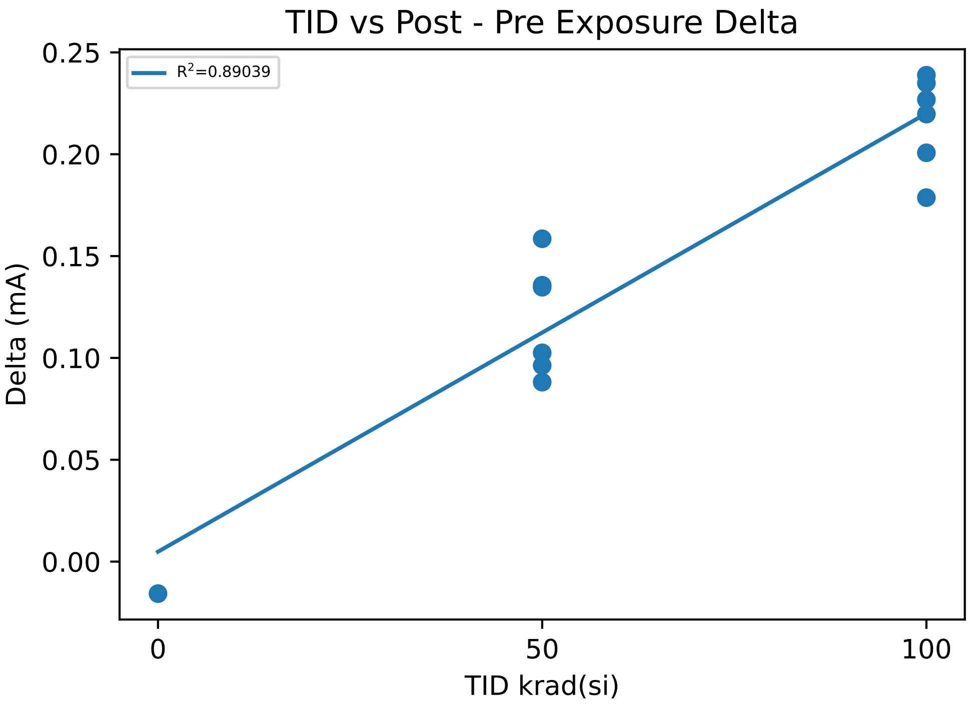
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.4859	4.6124	0.1265
60	50	Biased	4.4865	4.6385	0.152
61	50	Biased	4.5355	4.6603	0.1248
63	100	Biased	4.537	4.8525	0.3155
64	100	Biased	4.4908	4.752	0.2612
65	100	Biased	4.4772	4.7294	0.2522
66	50	Unbiased	4.5245	4.6328	0.1083
67	50	Unbiased	4.4542	4.5564	0.1022
68	50	Unbiased	4.6031	4.7865	0.1834
69	100	Unbiased	4.5996	4.9068	0.3072
70	100	Unbiased	4.6063	4.9053	0.299
71	100	Unbiased	4.4855	4.7066	0.2211
72	0	Control	4.3754	4.3614	-0.014

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3754	4.3754	4.3754		4.3614	4.3614	4.3614		-0.014	-0.014	-0.014	
50	4.4542	4.5149	4.6031	0.052207	4.5564	4.6478	4.7865	0.076567	0.1022	0.13287	0.1834	0.03023
100	4.4772	4.5327	4.6063	0.058266	4.7066	4.8088	4.9068	0.090334	0.2211	0.27603	0.3155	0.037046

Device Test: 37.5 Iq HS BOOT IIM Interlock Disable VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

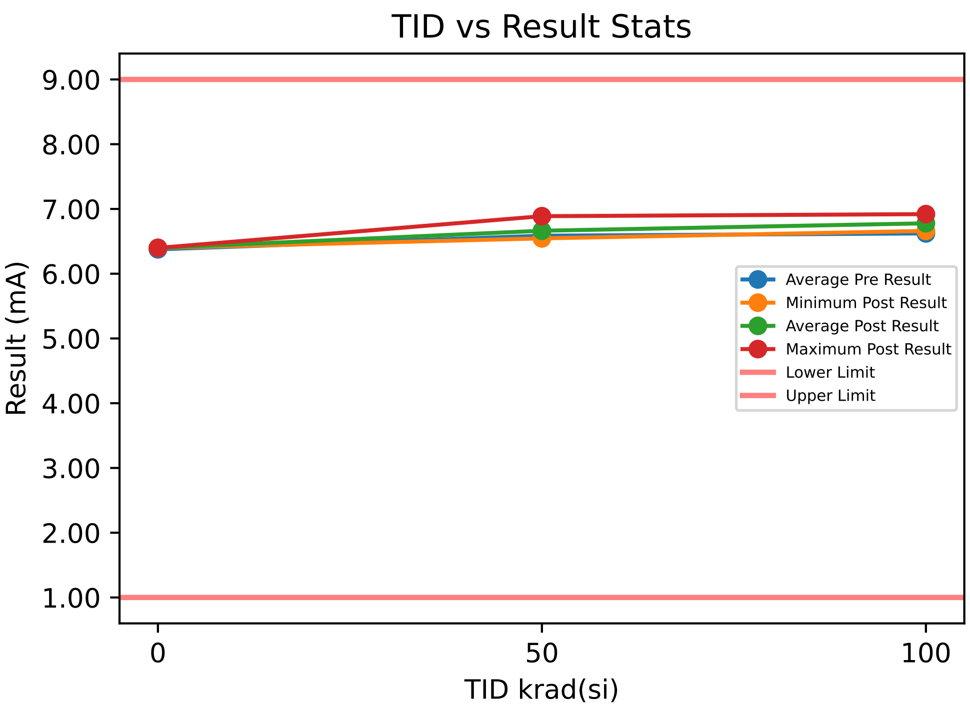
Test Results (Lower Limit = 1.0, Upper Limit = 6.3 (mA))

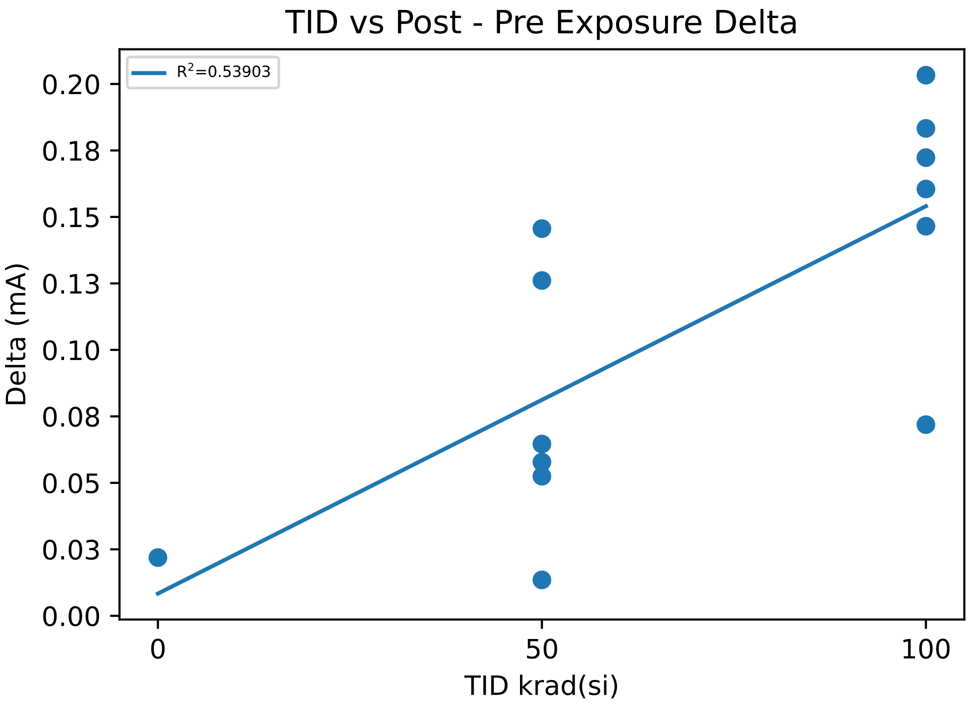
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.7404	3.8367	0.0963
60	50	Biased	3.8546	3.9893	0.1347
61	50	Biased	3.7267	3.8852	0.1585
63	100	Biased	3.8798	4.1147	0.2349
64	100	Biased	3.7679	3.9466	0.1787
65	100	Biased	3.9969	4.2237	0.2268
66	50	Unbiased	4.0373	4.1254	0.0881
67	50	Unbiased	3.9736	4.1093	0.1357
68	50	Unbiased	3.8562	3.9587	0.1025
69	100	Unbiased	3.8628	4.0635	0.2007
70	100	Unbiased	3.912	4.1508	0.2388
71	100	Unbiased	3.947	4.1667	0.2197
72	0	Control	3.771	3.7553	-0.0157

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.771	3.771	3.771		3.7553	3.7553	3.7553		-0.0157	-0.0157	-0.0157	
50	3.7267	3.8648	4.0373	0.12355	3.8367	3.9841	4.1254	0.11647	0.0881	0.1193	0.1585	0.027667
100	3.7679	3.8944	3.9969	0.078482	3.9466	4.111	4.2237	0.096628	0.1787	0.2166	0.2388	0.022937

Device Test: 37.6 Iop LS VIN PWM 500kHz VIN_14V





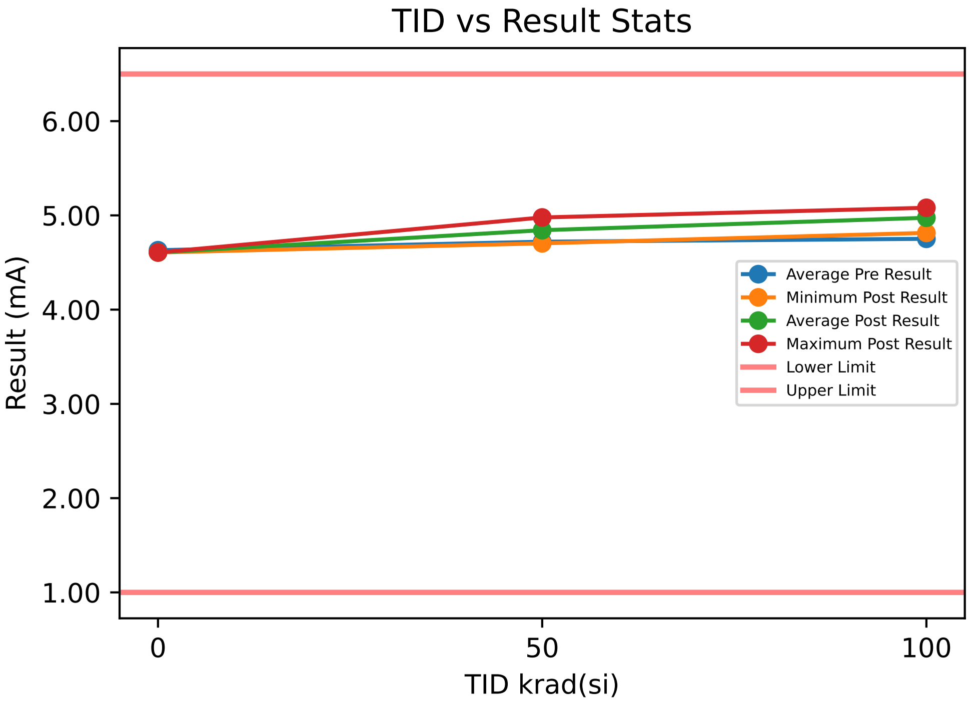
Test Results (Lower Limit = 1.0, Upper Limit = 9.0 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.4932	6.551	0.0578
60	50	Biased	6.4629	6.589	0.1261
61	50	Biased	6.5865	6.639	0.0525
63	100	Biased	6.6699	6.8422	0.1723
64	100	Biased	6.4775	6.6608	0.1833
65	100	Biased	6.563	6.7095	0.1465
66	50	Unbiased	6.7032	6.7678	0.0646
67	50	Unbiased	6.5319	6.5454	0.0135
68	50	Unbiased	6.7428	6.8884	0.1456
69	100	Unbiased	6.704	6.8645	0.1605
70	100	Unbiased	6.7167	6.92	0.2033
71	100	Unbiased	6.6006	6.6725	0.0719
72	0	Control	6.3763	6.3982	0.0219

Test Statistics (mA)

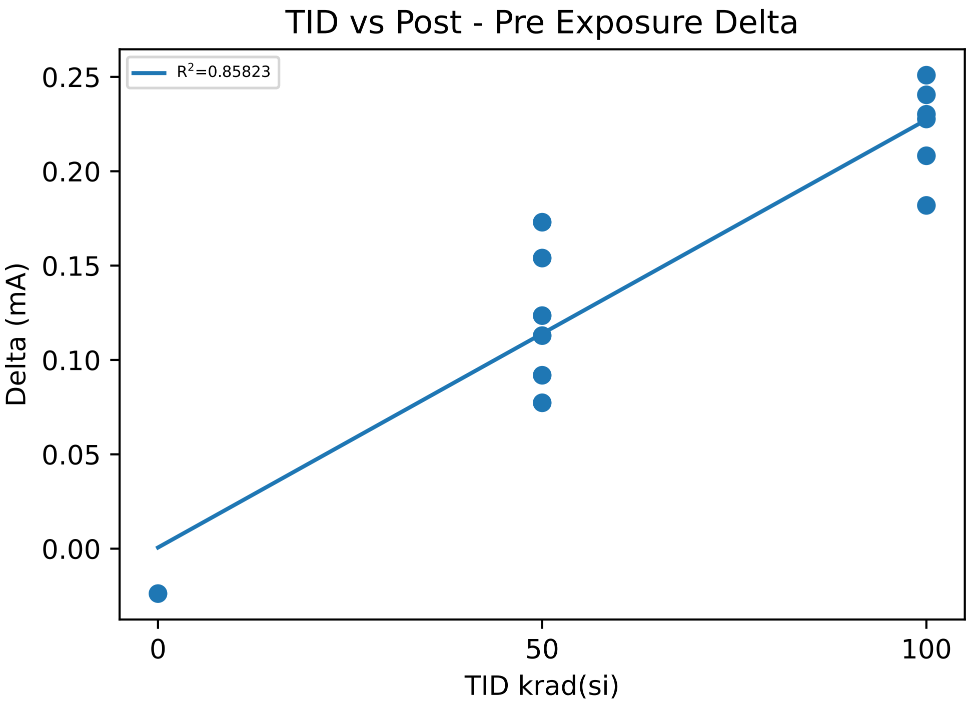
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.3763	6.3763	6.3763		6.3982	6.3982	6.3982		0.0219	0.0219	0.0219	
50	6.4629	6.5867	6.7428	0.11403	6.5454	6.6634	6.8884	0.13727	0.0135	0.076683	0.1456	0.04954
100	6.4775	6.622	6.7167	0.092526	6.6608	6.7782	6.92	0.11075	0.0719	0.1563	0.2033	0.045675

Device Test: 37.7 Iop HS BOOT PWM 500kHz VIN_14V



Test Results (Lower Limit = 1.0, Upper Limit = 6.5 (mA))

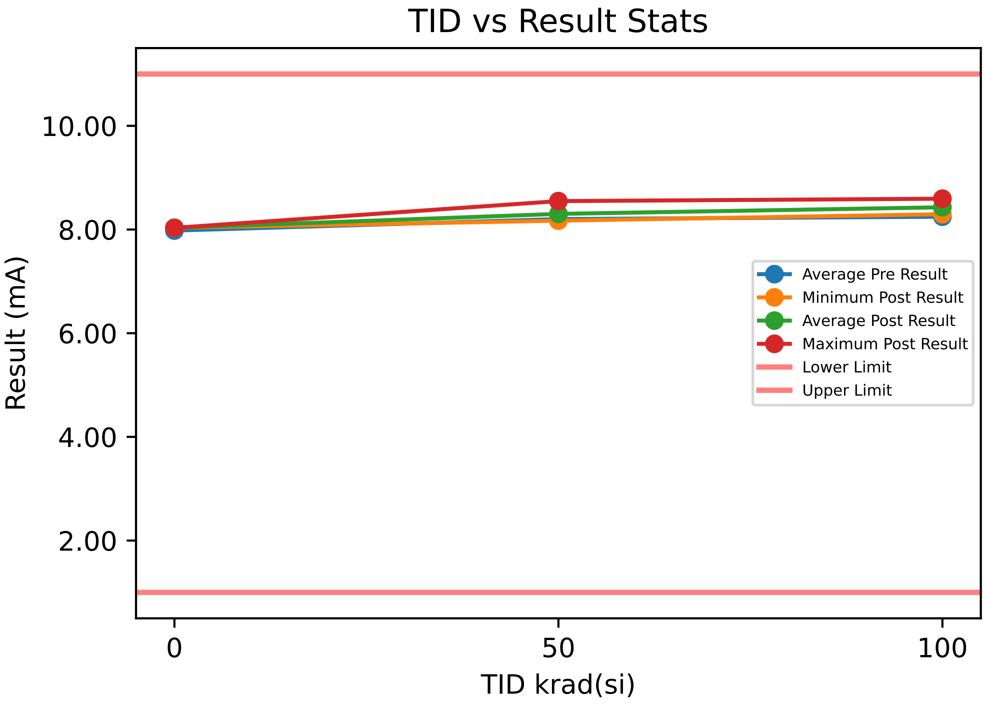
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.5903	4.7032	0.1129
60	50	Biased	4.7126	4.8361	0.1235
61	50	Biased	4.5782	4.7512	0.173
63	100	Biased	4.7335	4.9844	0.2509
64	100	Biased	4.6322	4.8141	0.1819
65	100	Biased	4.8528	5.0805	0.2277
66	50	Unbiased	4.8985	4.9758	0.0773
67	50	Unbiased	4.8239	4.9779	0.154
68	50	Unbiased	4.7209	4.8128	0.0919
69	100	Unbiased	4.7177	4.9259	0.2082
70	100	Unbiased	4.7703	5.0005	0.2302
71	100	Unbiased	4.8014	5.0419	0.2405
72	0	Control	4.6303	4.6065	-0.0238

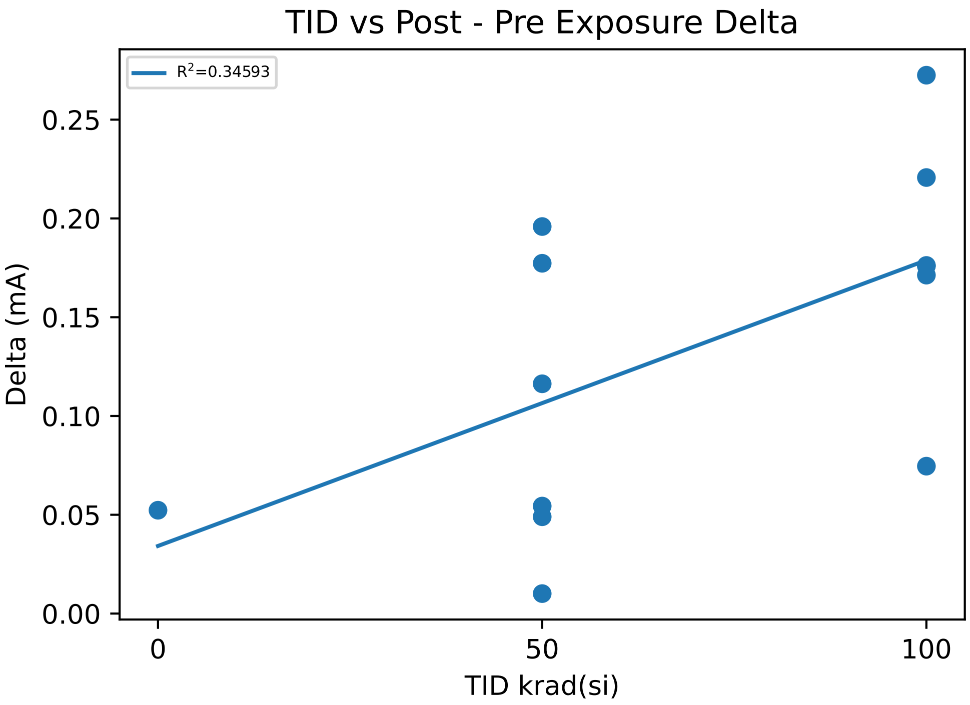


Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6303	4.6303	4.6303		4.6065	4.6065	4.6065		-0.0238	-0.0238	-0.0238	
50	4.5782	4.7207	4.8985	0.12621	4.7032	4.8428	4.9779	0.11381	0.0773	0.1221	0.173	0.036371
100	4.6322	4.7513	4.8528	0.0759	4.8141	4.9745	5.0805	0.094491	0.1819	0.22323	0.2509	0.024765

Device Test: 37.8 Iop LS VIN PWM 1MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

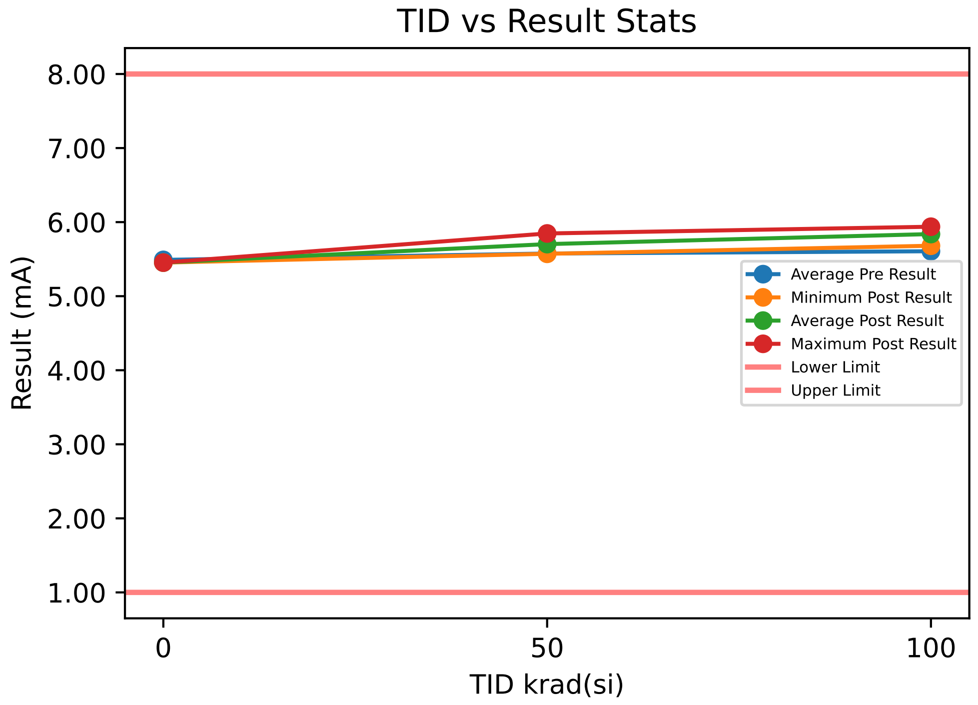
Test Results (Lower Limit = 1.0, Upper Limit = 11.0 (mA))

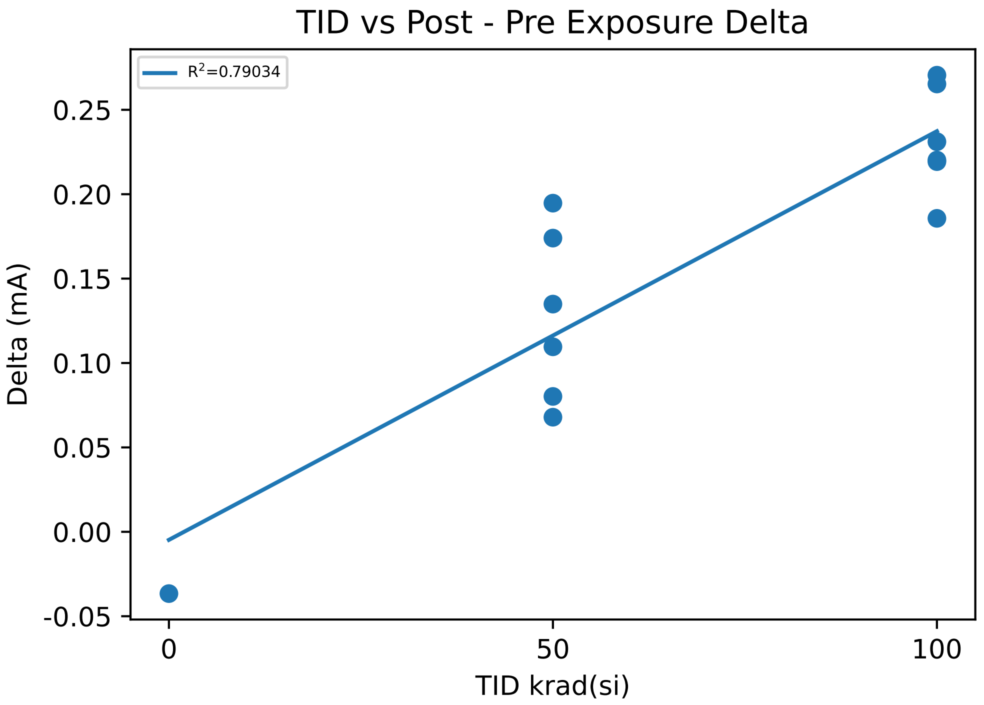
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	8.1217	8.1761	0.0544
60	50	Biased	8.057	8.2343	0.1773
61	50	Biased	8.2126	8.2616	0.049
63	100	Biased	8.2992	8.4751	0.1759
64	100	Biased	8.0744	8.2951	0.2207
65	100	Biased	8.1965	8.3727	0.1762
66	50	Unbiased	8.3018	8.4181	0.1163
67	50	Unbiased	8.1607	8.1708	0.0101
68	50	Unbiased	8.3523	8.5482	0.1959
69	100	Unbiased	8.3481	8.5194	0.1713
70	100	Unbiased	8.322	8.5945	0.2725
71	100	Unbiased	8.2428	8.3174	0.0746
72	0	Control	7.9797	8.032	0.0523

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.9797	7.9797	7.9797		8.032	8.032	8.032		0.0523	0.0523	0.0523	
50	8.057	8.201	8.3523	0.11121	8.1708	8.3015	8.5482	0.15058	0.0101	0.1005	0.1959	0.075098
100	8.0744	8.2472	8.3481	0.10093	8.2951	8.429	8.5945	0.11937	0.0746	0.18187	0.2725	0.065434

Device Test: 37.9 Iop HS BOOT PWM 1MHz VIN_14V





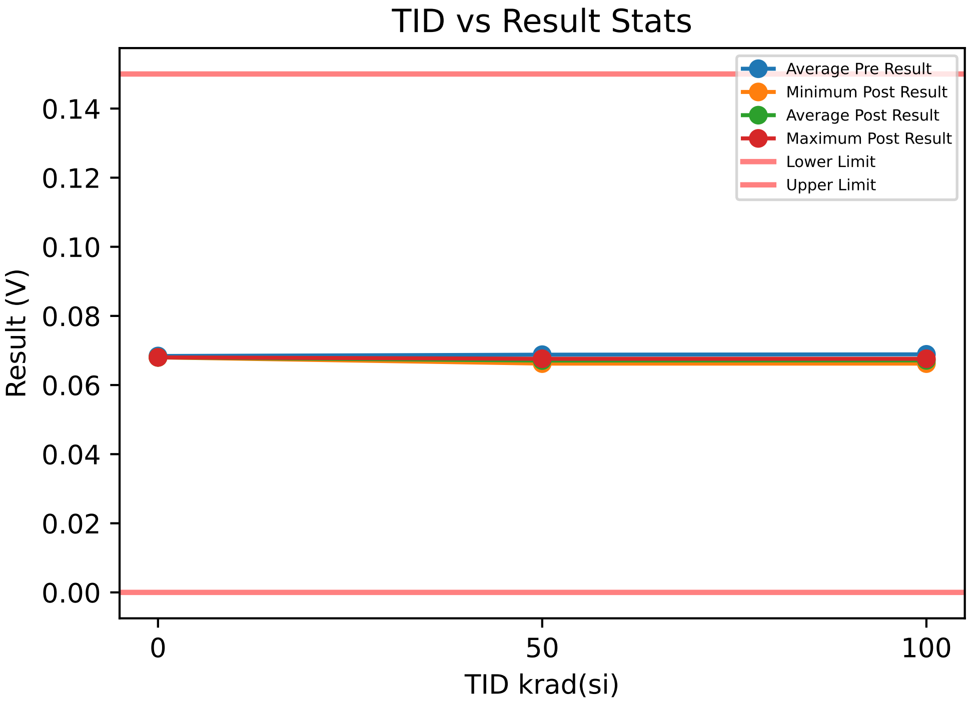
Test Results (Lower Limit = 1.0, Upper Limit = 8.0 (mA))

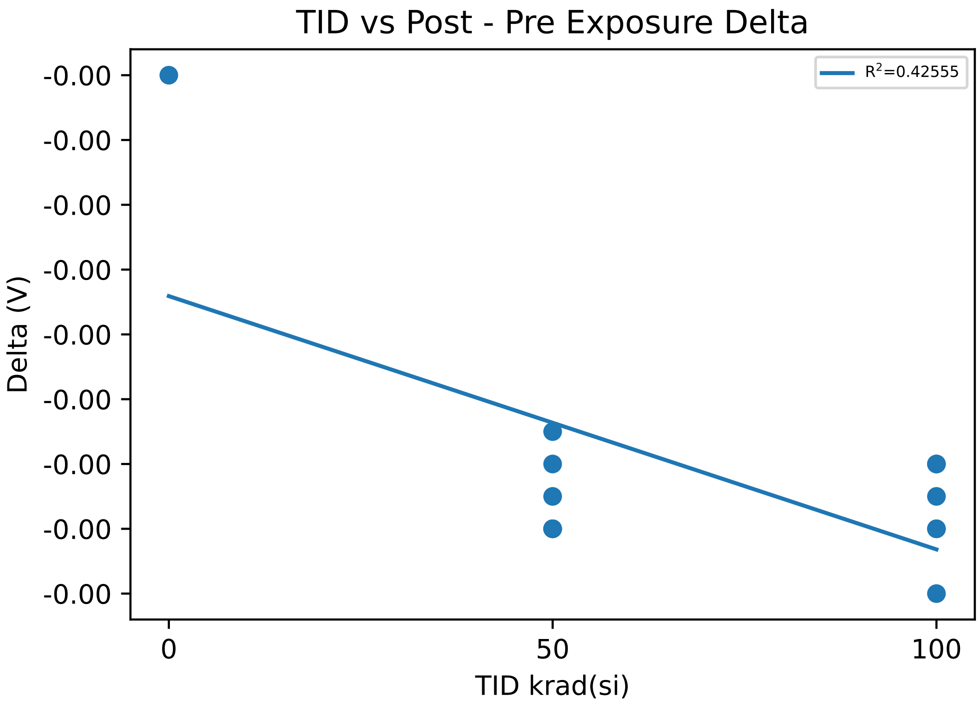
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.4371	5.572	0.1349
60	50	Biased	5.572	5.6816	0.1096
61	50	Biased	5.4284	5.6231	0.1947
63	100	Biased	5.5846	5.8551	0.2705
64	100	Biased	5.4953	5.681	0.1857
65	100	Biased	5.7066	5.9377	0.2311
66	50	Unbiased	5.7586	5.8265	0.0679
67	50	Unbiased	5.6728	5.8468	0.174
68	50	Unbiased	5.5868	5.667	0.0802
69	100	Unbiased	5.5716	5.7918	0.2202
70	100	Unbiased	5.629	5.8483	0.2193
71	100	Unbiased	5.653	5.9183	0.2653
72	0	Control	5.4899	5.4533	-0.0366

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4899	5.4899	5.4899		5.4533	5.4533	5.4533		-0.0366	-0.0366	-0.0366	
50	5.4284	5.5759	5.7586	0.12956	5.572	5.7028	5.8468	0.11066	0.0679	0.12688	0.1947	0.050676
100	5.4953	5.6067	5.7066	0.073146	5.681	5.8387	5.9377	0.093346	0.1857	0.23202	0.2705	0.031737

Device Test: 45.0 VOL LO VIN_10V





Test Results (Lower Limit = 0.0,
Upper Limit = 0.15 (V))

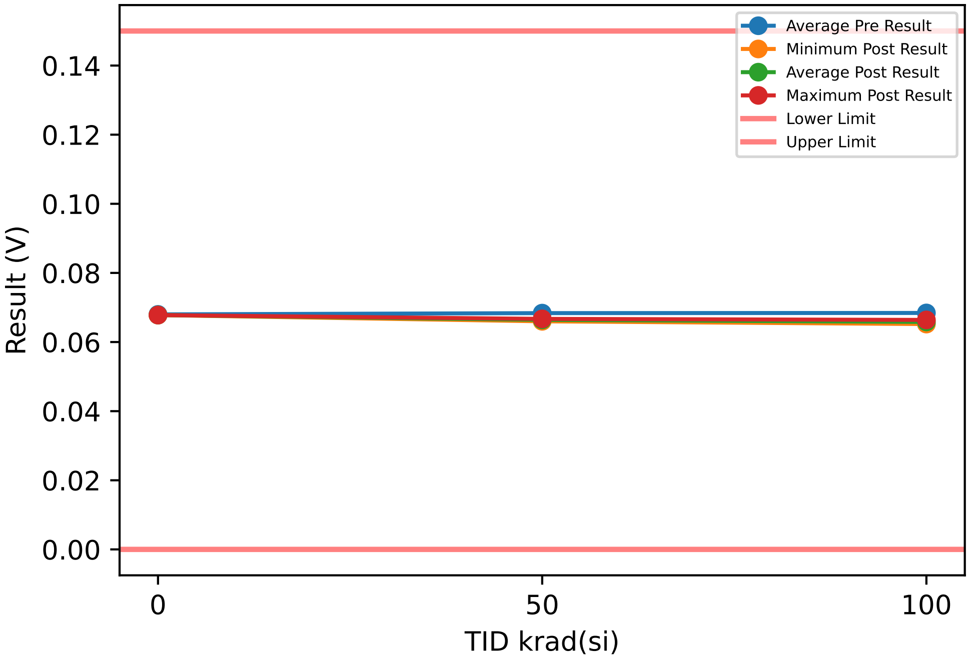
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0688	0.067	-0.0018
60	50	Biased	0.068	0.0662	-0.0018
61	50	Biased	0.0684	0.0666	-0.0018
63	100	Biased	0.0692	0.0676	-0.0016
64	100	Biased	0.068	0.0662	-0.0018
65	100	Biased	0.069	0.0673	-0.0017
66	50	Unbiased	0.0693	0.0676	-0.0017
67	50	Unbiased	0.0691	0.0676	-0.0015
68	50	Unbiased	0.0691	0.0675	-0.0016
69	100	Unbiased	0.0688	0.067	-0.0018
70	100	Unbiased	0.0695	0.0675	-0.002
71	100	Unbiased	0.0688	0.0672	-0.0016
72	0	Control	0.0684	0.068	-0.0004

Test Statistics (V)

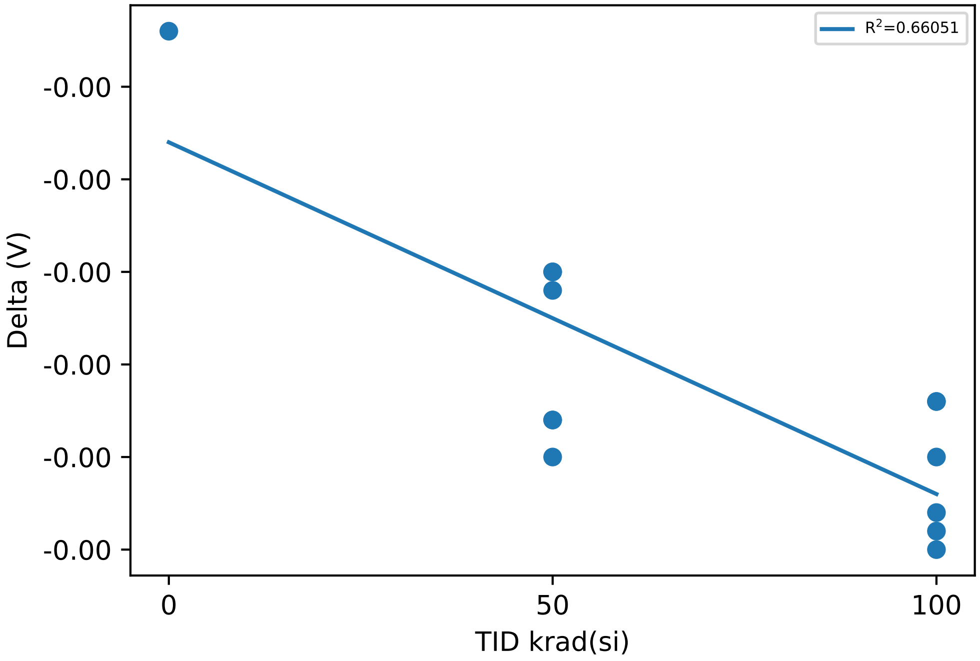
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0684	0.0684	0.0684		0.068	0.068	0.068		-0.0004	-0.0004	-0.0004	
50	0.068	0.068783	0.0693	0.00049565	0.0662	0.067083	0.0676	0.00058793	-0.0018	-0.0017	-0.0015	0.00012649
100	0.068	0.068883	0.0695	0.00050761	0.0662	0.067133	0.0676	0.00050465	-0.002	-0.00175	-0.0016	0.00015166

Device Test: 45.1 VOL HO VIN_10V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



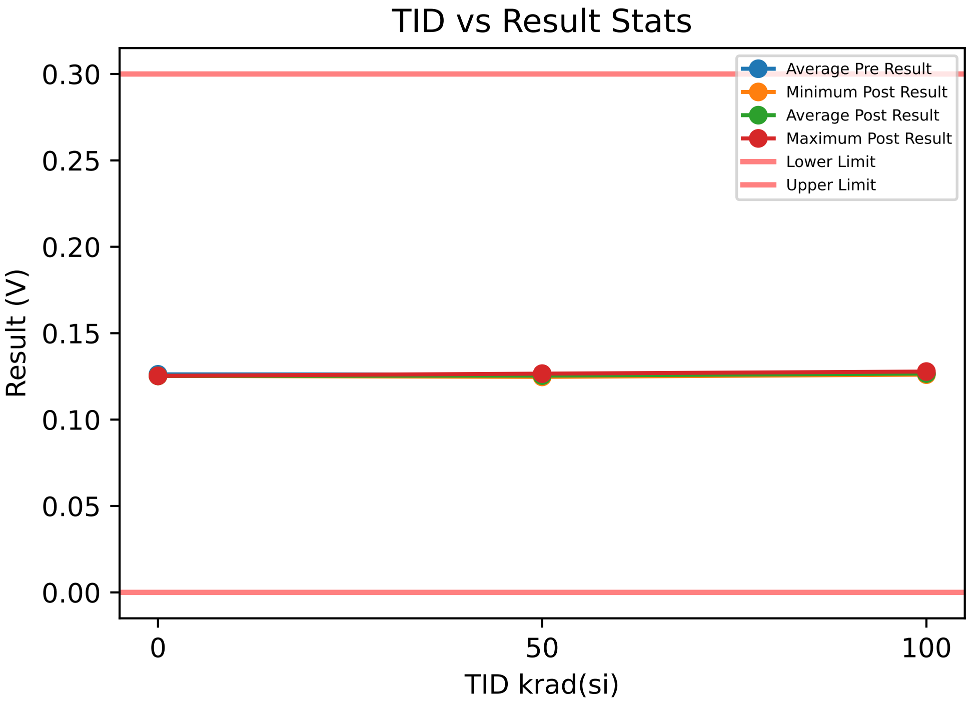
Test Results (Lower Limit = 0.0, Upper Limit = 0.15 (V))

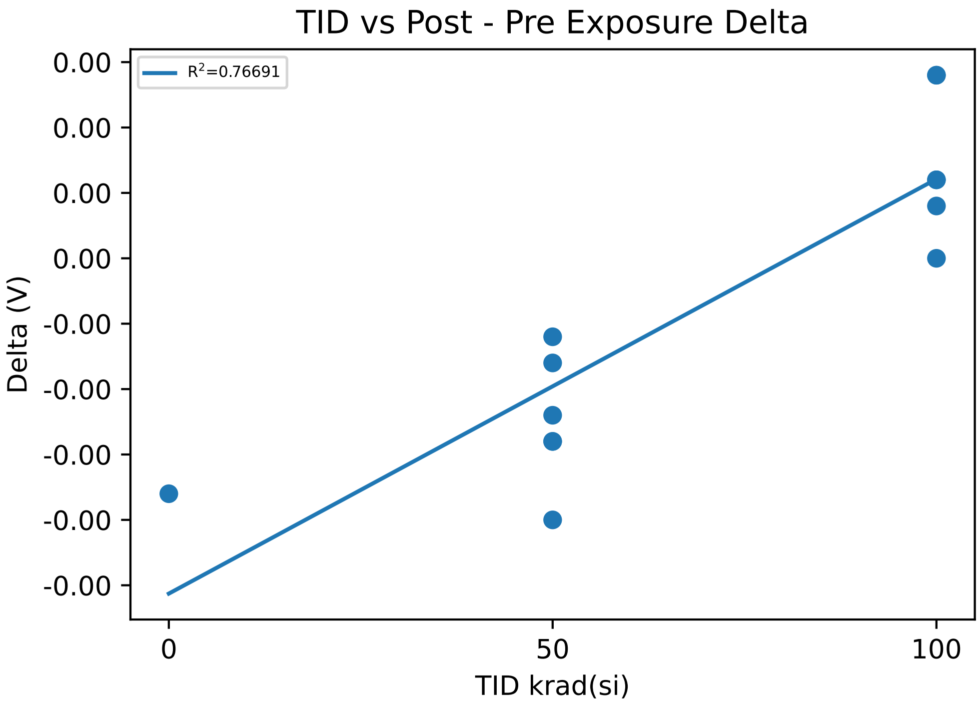
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0683	0.066	-0.0023
60	50	Biased	0.0687	0.0664	-0.0023
61	50	Biased	0.0687	0.0662	-0.0025
63	100	Biased	0.0683	0.0655	-0.0028
64	100	Biased	0.0689	0.066	-0.0029
65	100	Biased	0.0682	0.0652	-0.003
66	50	Unbiased	0.0682	0.0666	-0.0016
67	50	Unbiased	0.0681	0.0666	-0.0015
68	50	Unbiased	0.0682	0.0667	-0.0015
69	100	Unbiased	0.0686	0.0664	-0.0022
70	100	Unbiased	0.0681	0.0659	-0.0022
71	100	Unbiased	0.0684	0.0659	-0.0025
72	0	Control	0.068	0.0678	-0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.068	0.068	0.068		0.0678	0.0678	0.0678		-0.0002	-0.0002	-0.0002	
50	0.0681	0.068367	0.0687	0.00026583	0.066	0.066417	0.0667	0.00027142	-0.0025	-0.00195	-0.0015	0.00046368
100	0.0681	0.068417	0.0689	0.00029269	0.0652	0.065817	0.0664	0.00041673	-0.003	-0.0026	-0.0022	0.00035214

Device Test: 45.2 VOH Delta LO VIN_10V





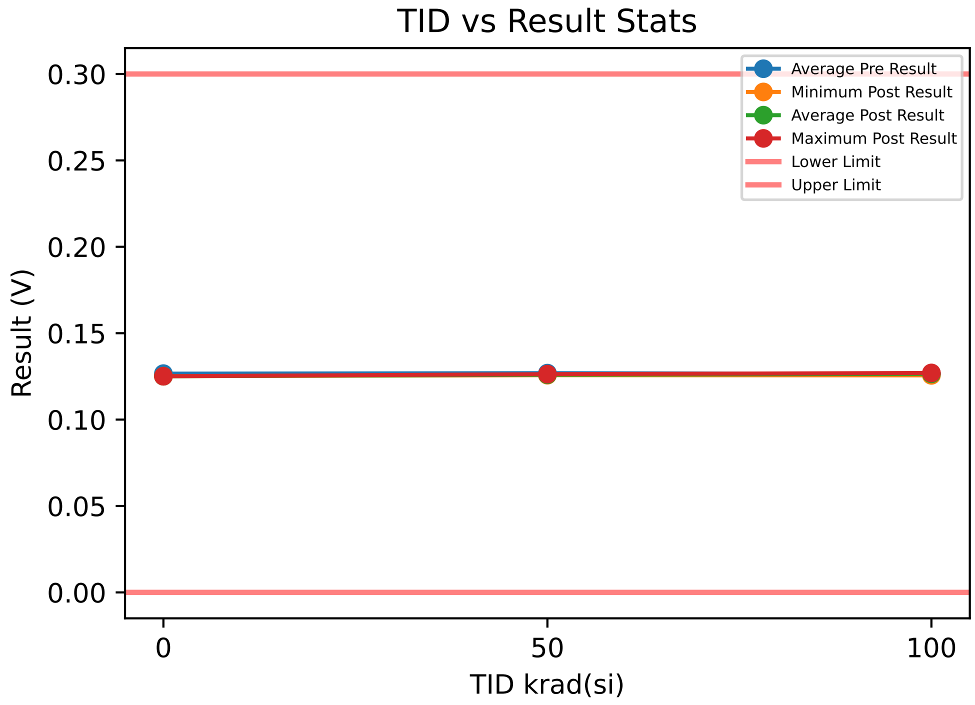
Test Results (Lower Limit = 0.0, Upper Limit = 0.3 (V))

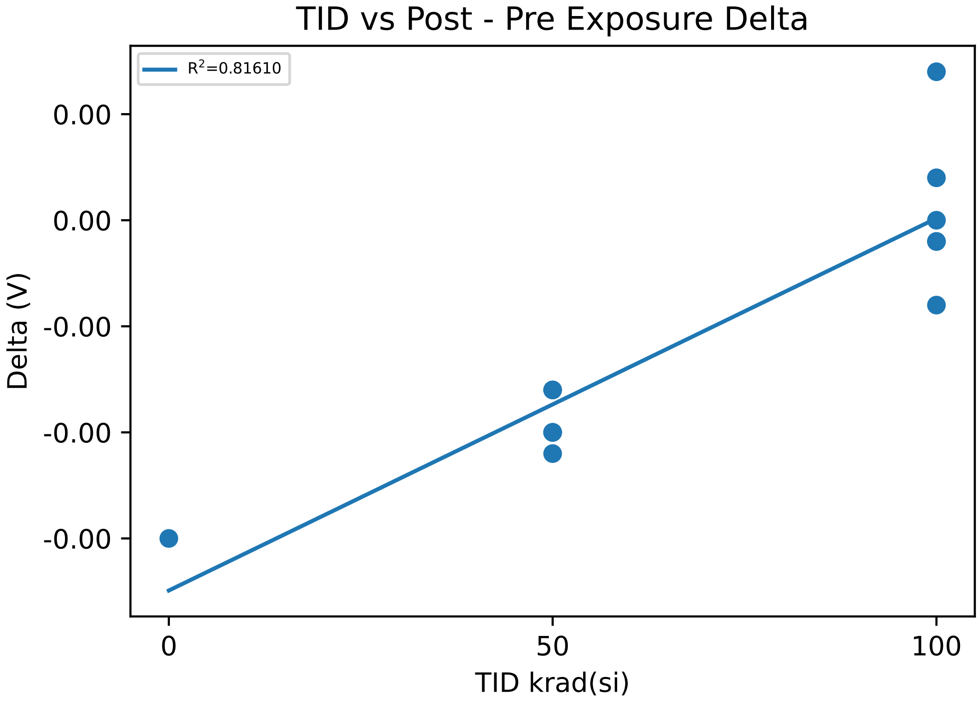
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.1257	0.1247	-0.001
60	50	Biased	0.1261	0.1254	-0.0007
61	50	Biased	0.1256	0.1249	-0.0007
63	100	Biased	0.1254	0.1261	0.0007
64	100	Biased	0.126	0.1263	0.0003
65	100	Biased	0.126	0.126	0
66	50	Unbiased	0.1262	0.1256	-0.0006
67	50	Unbiased	0.1269	0.1266	-0.0003
68	50	Unbiased	0.1259	0.1255	-0.0004
69	100	Unbiased	0.1265	0.1268	0.0003
70	100	Unbiased	0.1266	0.1268	0.0002
71	100	Unbiased	0.1271	0.1278	0.0007
72	0	Control	0.1262	0.1253	-0.0009

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1262	0.1262	0.1262		0.1253	0.1253	0.1253		-0.0009	-0.0009	-0.0009	
50	0.1256	0.12607	0.1269	0.00046762	0.1247	0.12545	0.1266	0.00066558	-0.001	-0.00061667	-0.0003	0.00024833
100	0.1254	0.12627	0.1271	0.00059217	0.126	0.12663	0.1278	0.00066533	0	0.00036667	0.0007	0.00028048

Device Test: 45.3 VOH Delta HO VIN_10V





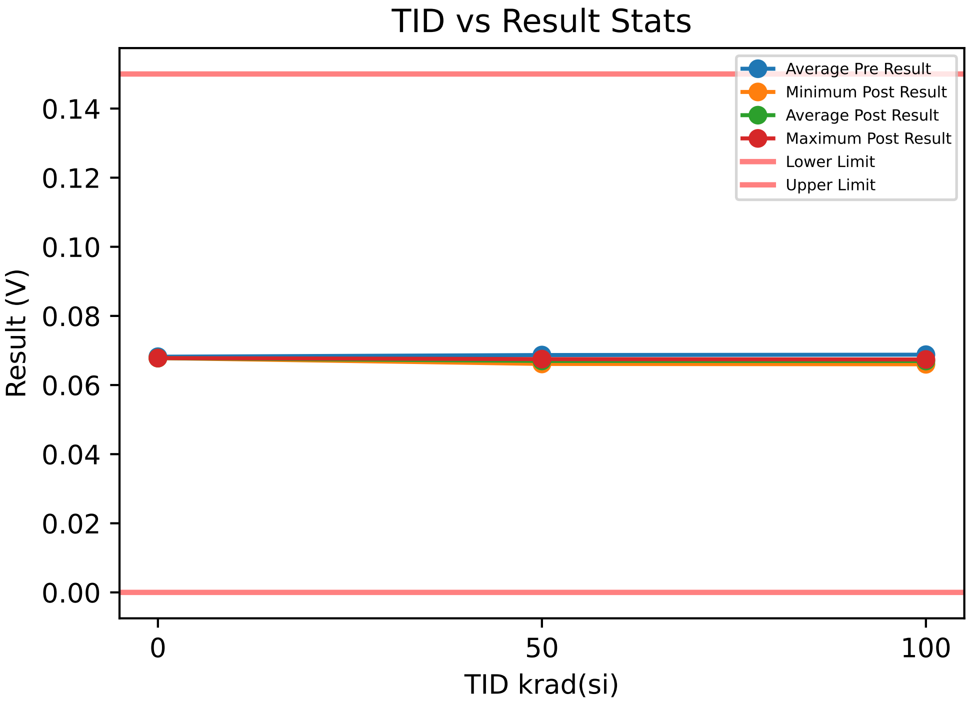
Test Results (Lower Limit = 0.0, Upper Limit = 0.3 (V))

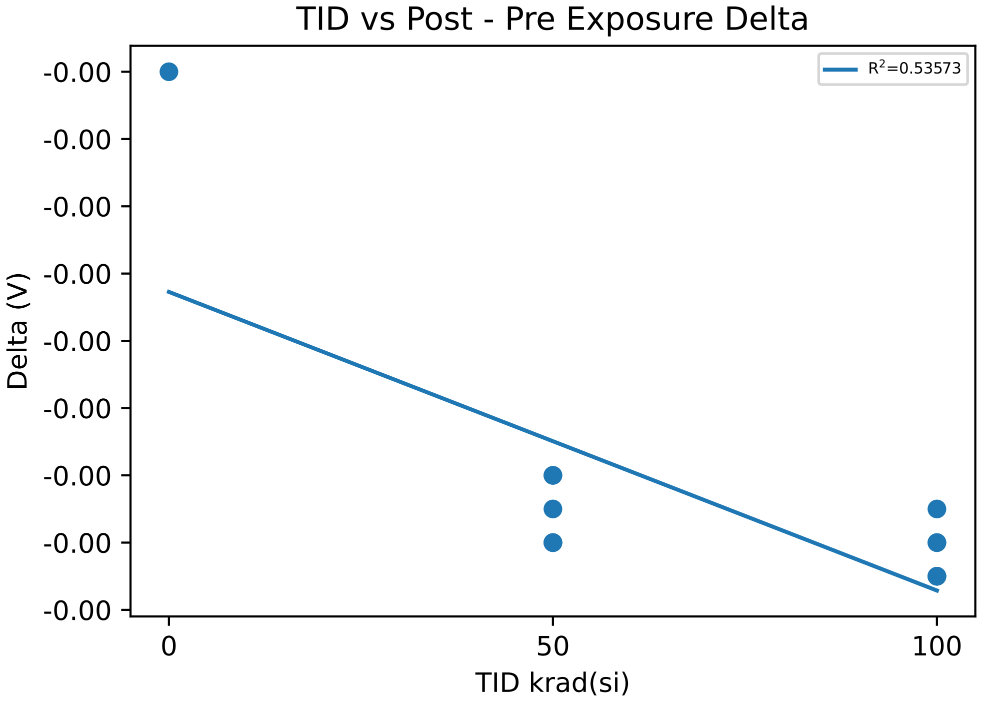
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.1267	0.1257	-0.001
60	50	Biased	0.1274	0.1263	-0.0011
61	50	Biased	0.1267	0.1257	-0.001
63	100	Biased	0.127	0.127	0
64	100	Biased	0.1271	0.127	-0.0001
65	100	Biased	0.1261	0.1263	0.0002
66	50	Unbiased	0.1271	0.1261	-0.001
67	50	Unbiased	0.1268	0.126	-0.0008
68	50	Unbiased	0.1266	0.1258	-0.0008
69	100	Unbiased	0.126	0.1267	0.0007
70	100	Unbiased	0.1264	0.1263	-0.0001
71	100	Unbiased	0.126	0.1256	-0.0004
72	0	Control	0.1266	0.1251	-0.0015

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1266	0.1266	0.1266		0.1251	0.1251	0.1251		-0.0015	-0.0015	-0.0015	
50	0.1266	0.12688	0.1274	0.00030605	0.1257	0.12593	0.1263	0.00024221	-0.0011	-0.00095	-0.0008	0.00012247
100	0.126	0.12643	0.1271	0.00050067	0.1256	0.12648	0.127	0.00053448	-0.0004	5e-05	0.0007	0.00037283

Device Test: 46.0 VOL LO VIN_12V





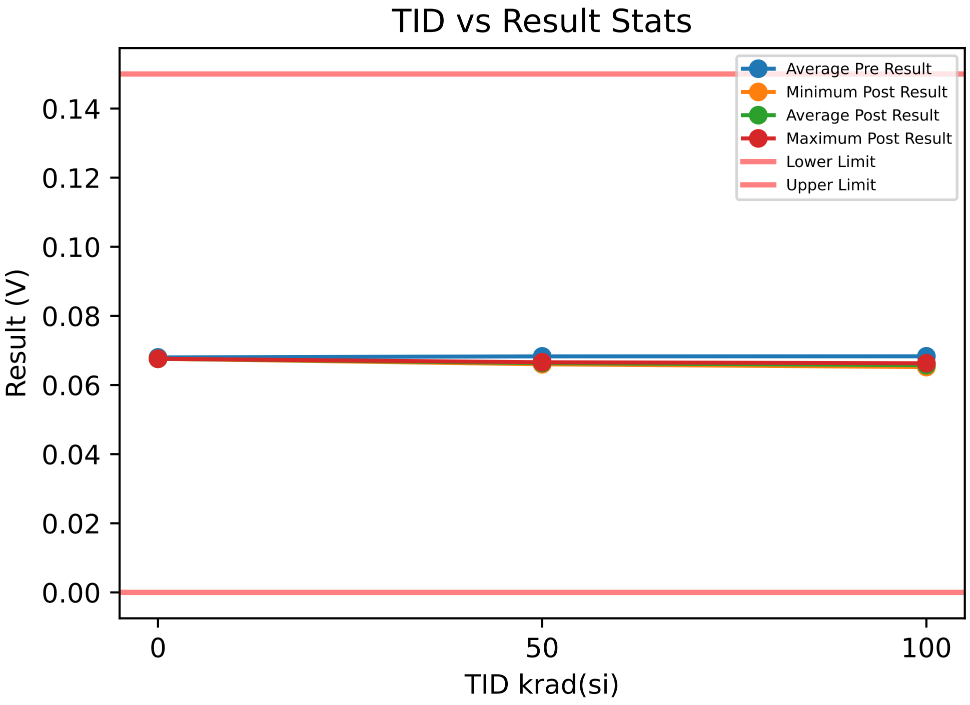
Test Results (Lower Limit = 0.0, Upper Limit = 0.15 (V))

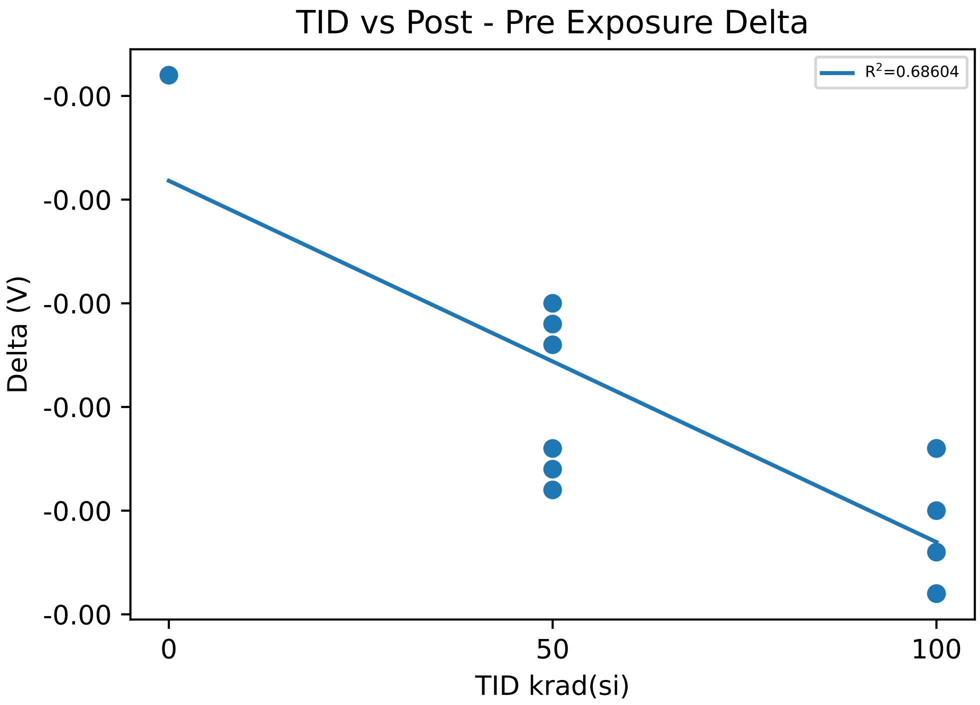
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0687	0.0669	-0.0018
60	50	Biased	0.0679	0.0661	-0.0018
61	50	Biased	0.0683	0.0665	-0.0018
63	100	Biased	0.0691	0.0674	-0.0017
64	100	Biased	0.0679	0.066	-0.0019
65	100	Biased	0.0689	0.0671	-0.0018
66	50	Unbiased	0.0692	0.0675	-0.0017
67	50	Unbiased	0.0691	0.0675	-0.0016
68	50	Unbiased	0.0689	0.0673	-0.0016
69	100	Unbiased	0.0687	0.0668	-0.0019
70	100	Unbiased	0.0693	0.0674	-0.0019
71	100	Unbiased	0.0688	0.067	-0.0018
72	0	Control	0.0682	0.0678	-0.0004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0682	0.0682	0.0682		0.0678	0.0678	0.0678		-0.0004	-0.0004	-0.0004	
50	0.0679	0.068683	0.0692	0.00049967	0.0661	0.066967	0.0675	0.00057504	-0.0018	-0.0017167	-0.0016	9.8319e-05
100	0.0679	0.068783	0.0693	0.00048339	0.066	0.06695	0.0674	0.00052058	-0.0019	-0.0018333	-0.0017	8.165e-05

Device Test: 46.1 VOL HO VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

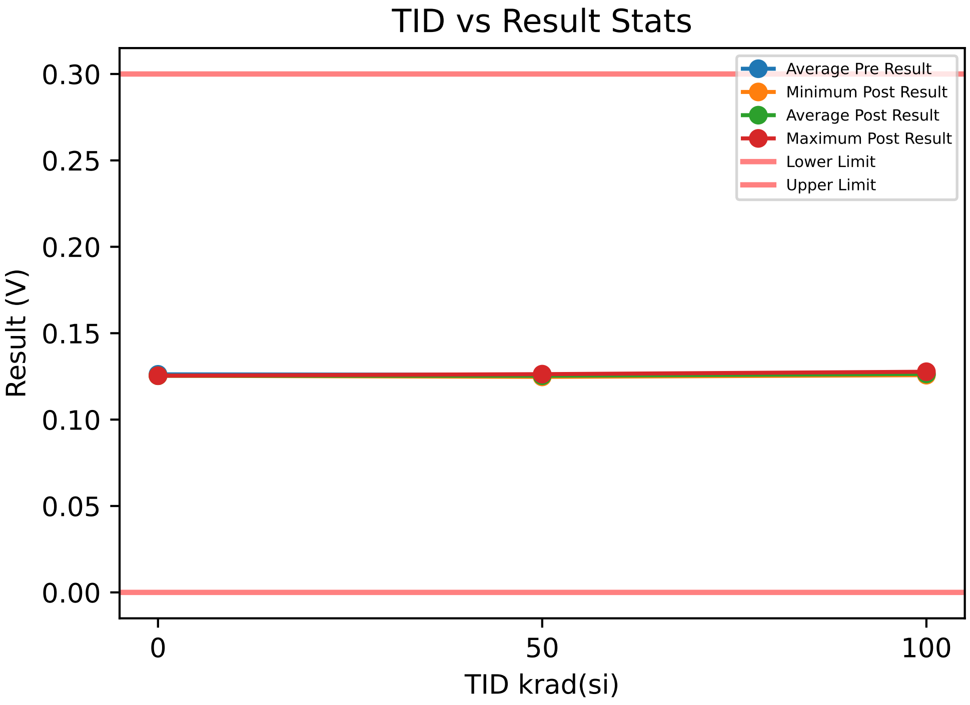
Test Results (Lower Limit = 0.0,
Upper Limit = 0.15 (V))

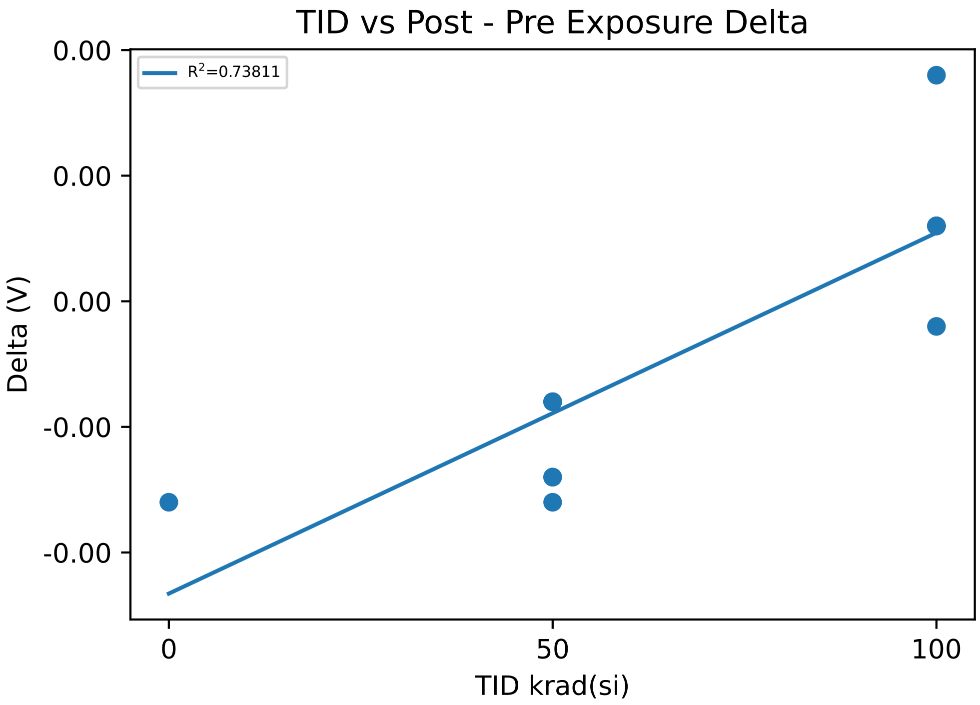
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0682	0.066	-0.0022
60	50	Biased	0.0686	0.0663	-0.0023
61	50	Biased	0.0686	0.0662	-0.0024
63	100	Biased	0.0682	0.0655	-0.0027
64	100	Biased	0.0688	0.0659	-0.0029
65	100	Biased	0.0681	0.0652	-0.0029
66	50	Unbiased	0.0682	0.0666	-0.0016
67	50	Unbiased	0.0681	0.0664	-0.0017
68	50	Unbiased	0.0681	0.0666	-0.0015
69	100	Unbiased	0.0685	0.0663	-0.0022
70	100	Unbiased	0.068	0.0658	-0.0022
71	100	Unbiased	0.0683	0.0658	-0.0025
72	0	Control	0.068	0.0676	-0.0004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.068	0.068	0.068		0.0676	0.0676	0.0676		-0.0004	-0.0004	-0.0004	
50	0.0681	0.0683	0.0686	0.00023664	0.066	0.06635	0.0666	0.00023452	-0.0024	-0.00195	-0.0015	0.0003937
100	0.068	0.068317	0.0688	0.00029269	0.0652	0.06575	0.0663	0.00037283	-0.0029	-0.0025667	-0.0022	0.00032042

Device Test: 46.2 VOH Delta LO VIN_12V





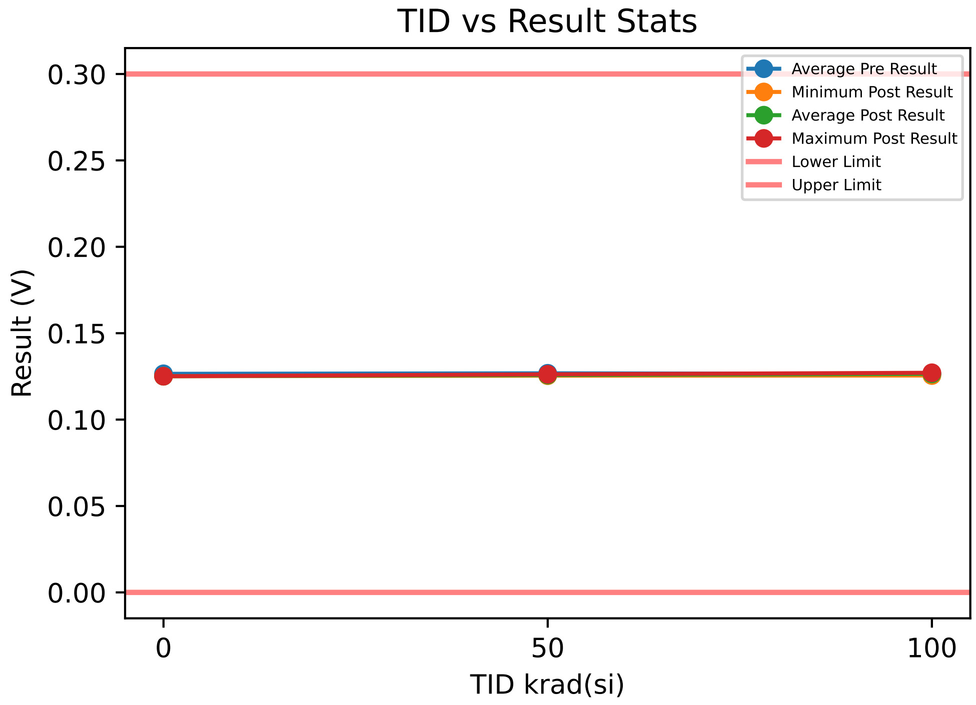
Test Results (Lower Limit = 0.0, Upper Limit = 0.3 (V))

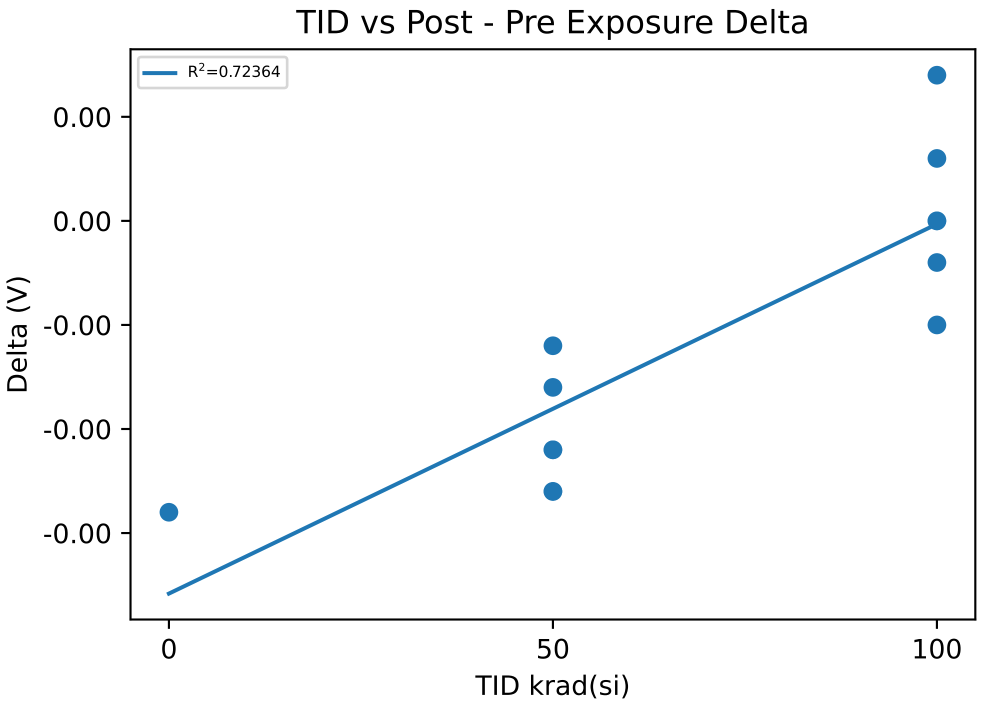
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.1254	0.1247	-0.0007
60	50	Biased	0.126	0.1252	-0.0008
61	50	Biased	0.1256	0.1249	-0.0007
63	100	Biased	0.1254	0.1257	0.0003
64	100	Biased	0.1259	0.1262	0.0003
65	100	Biased	0.1258	0.1257	-0.0001
66	50	Unbiased	0.1259	0.1255	-0.0004
67	50	Unbiased	0.1267	0.1263	-0.0004
68	50	Unbiased	0.1259	0.1255	-0.0004
69	100	Unbiased	0.1263	0.1266	0.0003
70	100	Unbiased	0.1264	0.1267	0.0003
71	100	Unbiased	0.1268	0.1277	0.0009
72	0	Control	0.1262	0.1254	-0.0008

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1262	0.1262	0.1262		0.1254	0.1254	0.1254		-0.0008	-0.0008	-0.0008	
50	0.1254	0.12592	0.1267	0.0004446	0.1247	0.12535	0.1263	0.0005648	-0.0008	-0.00056667	-0.0004	0.00018619
100	0.1254	0.1261	0.1268	0.000498	0.1257	0.12643	0.1277	0.00075277	-0.0001	0.00033333	0.0009	0.00032042

Device Test: 46.3 VOH Delta HO VIN_12V





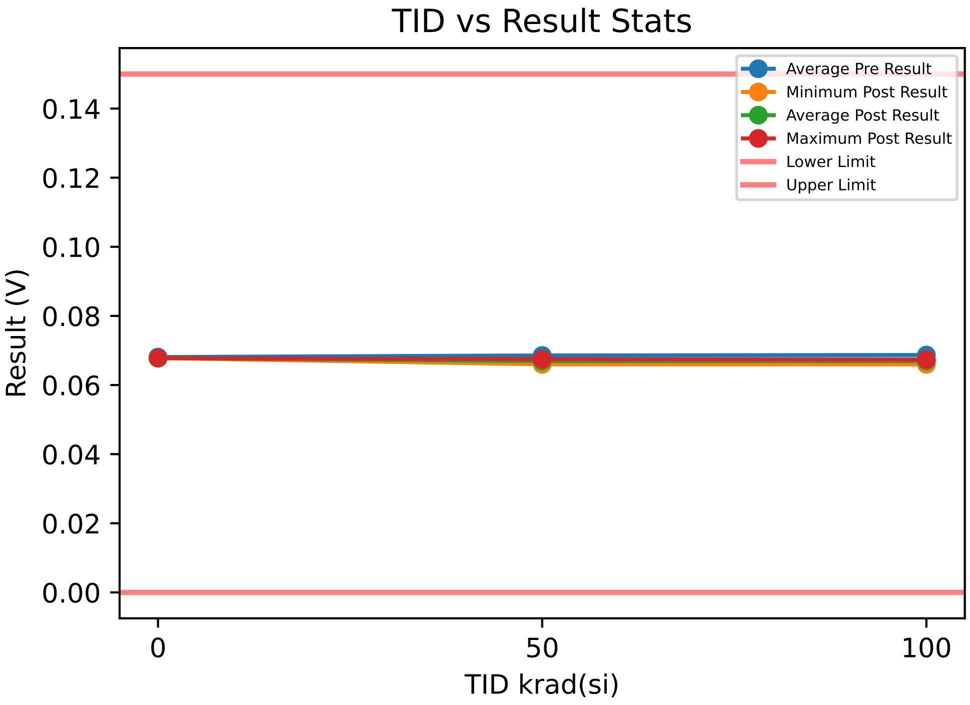
Test Results (Lower Limit = 0.0, Upper Limit = 0.3 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.1264	0.1256	-0.0008
60	50	Biased	0.1275	0.1262	-0.0013
61	50	Biased	0.1268	0.1255	-0.0013
63	100	Biased	0.1271	0.1269	-0.0002
64	100	Biased	0.1268	0.1271	0.0003
65	100	Biased	0.1261	0.1261	0
66	50	Unbiased	0.127	0.1259	-0.0011
67	50	Unbiased	0.1266	0.126	-0.0006
68	50	Unbiased	0.1265	0.1254	-0.0011
69	100	Unbiased	0.1261	0.1268	0.0007
70	100	Unbiased	0.1263	0.1263	0
71	100	Unbiased	0.126	0.1255	-0.0005
72	0	Control	0.1265	0.1251	-0.0014

Test Statistics (V)

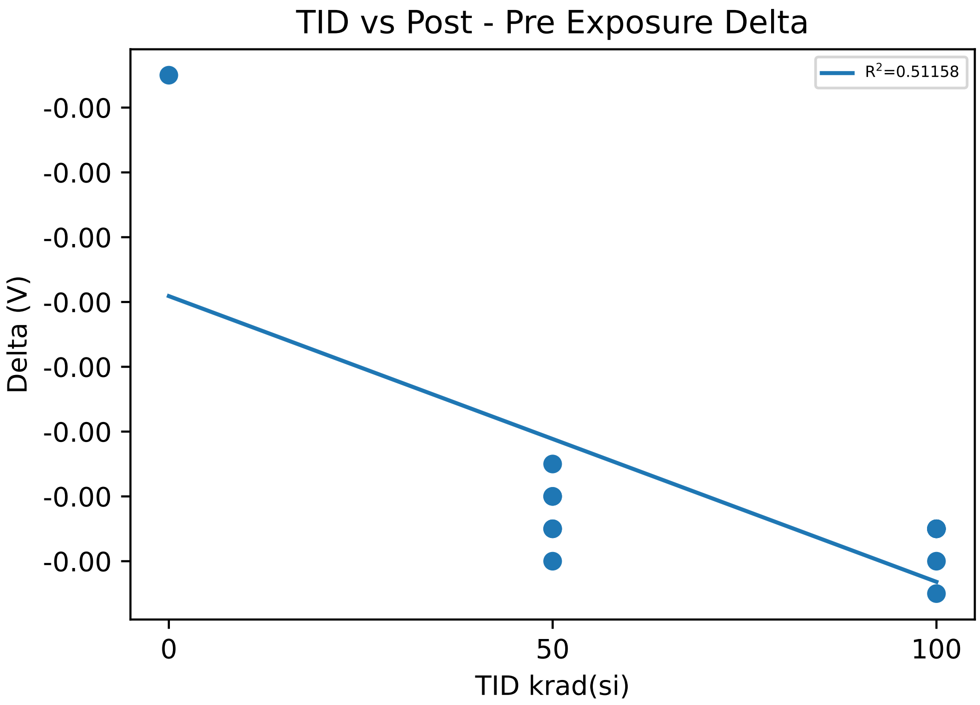
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1265	0.1265	0.1265		0.1251	0.1251	0.1251		-0.0014	-0.0014	-0.0014	
50	0.1264	0.1268	0.1275	0.00040497	0.1254	0.12577	0.1262	0.00031411	-0.0013	-0.0010333	-0.0006	0.00028048
100	0.126	0.1264	0.1271	0.00044721	0.1255	0.12645	0.1271	0.00059917	-0.0005	5e-05	0.0007	0.00041352

Device Test: 47.0 VOL LO VIN_14V



Test Results (Lower Limit = 0.0, Upper Limit = 0.15 (V))

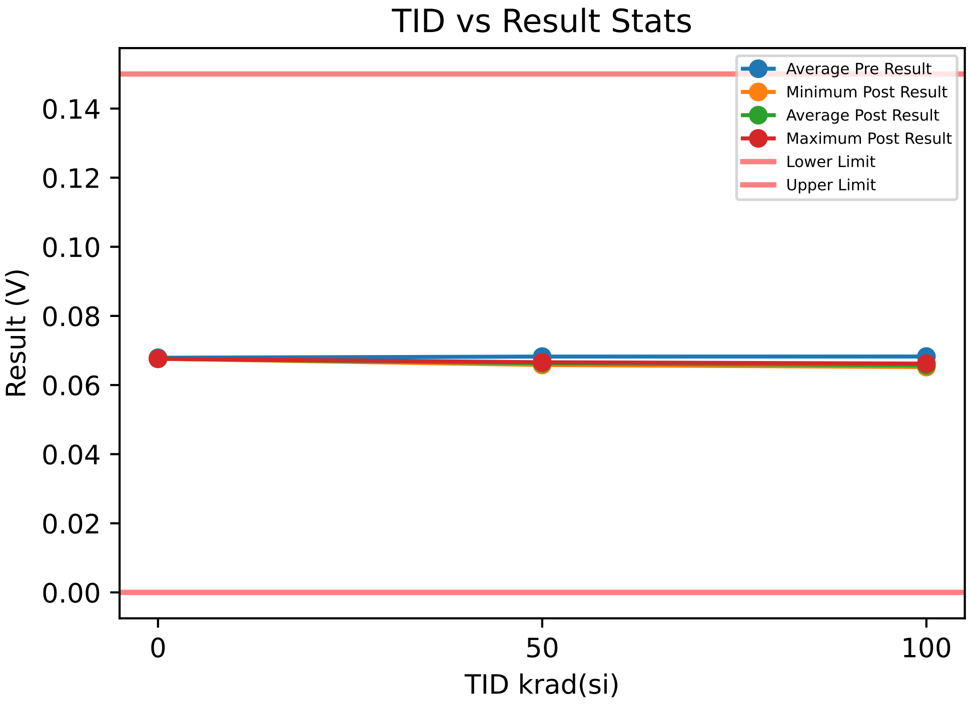
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0685	0.0668	-0.0017
60	50	Biased	0.0678	0.066	-0.0018
61	50	Biased	0.0681	0.0665	-0.0016
63	100	Biased	0.0691	0.0674	-0.0017
64	100	Biased	0.0677	0.066	-0.0017
65	100	Biased	0.0688	0.0671	-0.0017
66	50	Unbiased	0.0691	0.0674	-0.0017
67	50	Unbiased	0.069	0.0675	-0.0015
68	50	Unbiased	0.0689	0.0673	-0.0016
69	100	Unbiased	0.0686	0.0668	-0.0018
70	100	Unbiased	0.0692	0.0673	-0.0019
71	100	Unbiased	0.0687	0.067	-0.0017
72	0	Control	0.0681	0.0678	-0.0003

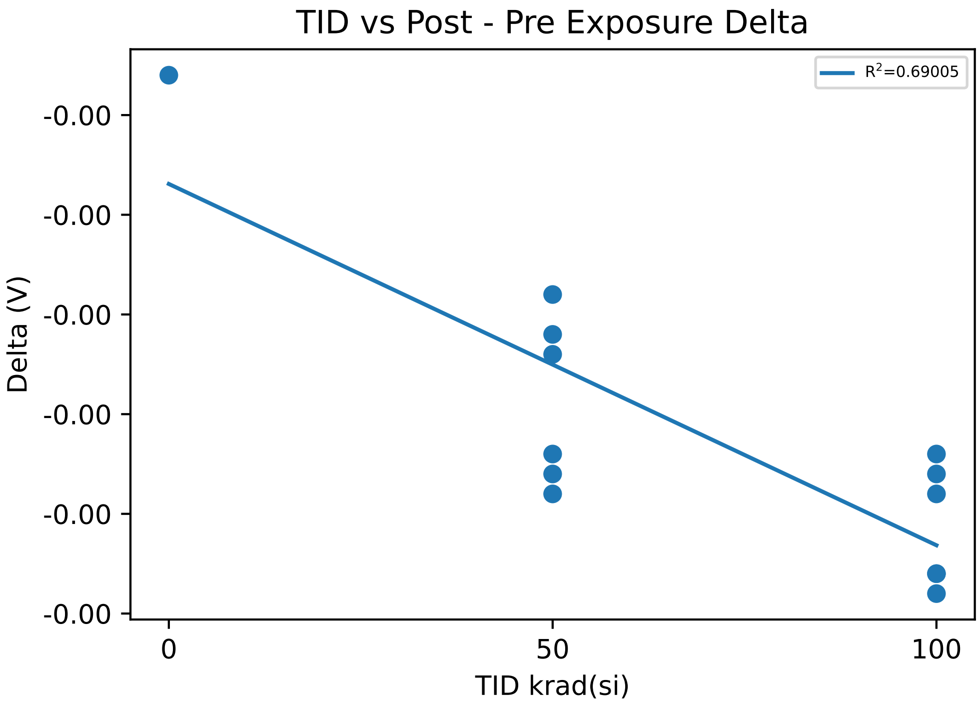


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0681	0.0681	0.0681		0.0678	0.0678	0.0678		-0.0003	-0.0003	-0.0003	
50	0.0678	0.068567	0.0691	0.00052789	0.066	0.066917	0.0675	0.00059133	-0.0018	-0.00165	-0.0015	0.00010488
100	0.0677	0.068683	0.0692	0.00053448	0.066	0.066933	0.0674	0.00050465	-0.0019	-0.00175	-0.0017	8.3666e-05

Device Test: 47.1 VOL HO VIN_14V





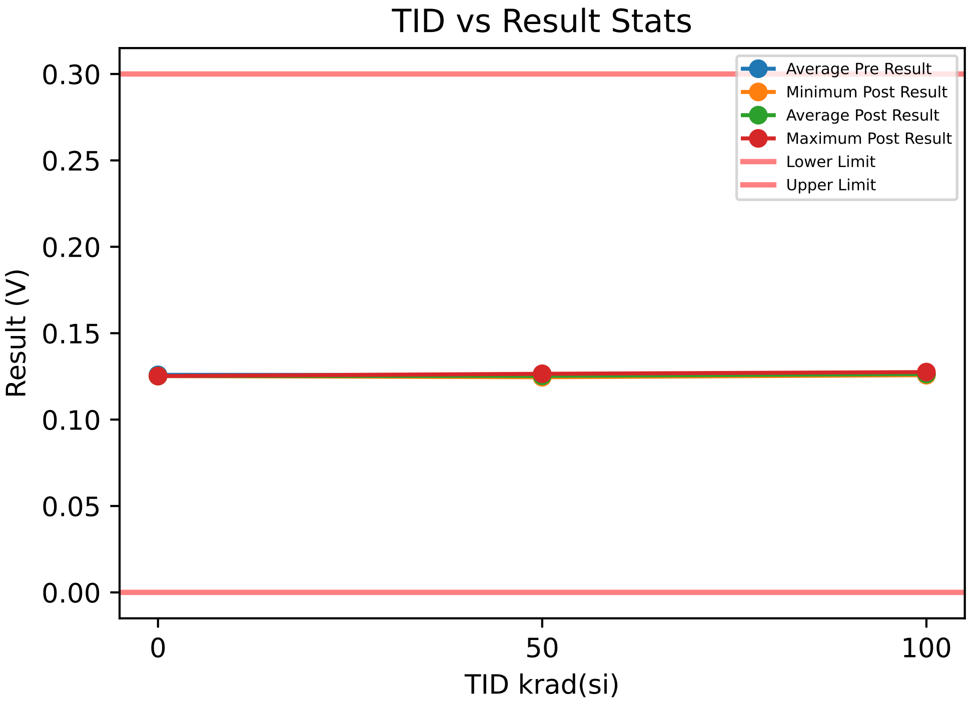
Test Results (Lower Limit = 0.0,
Upper Limit = 0.15 (V))

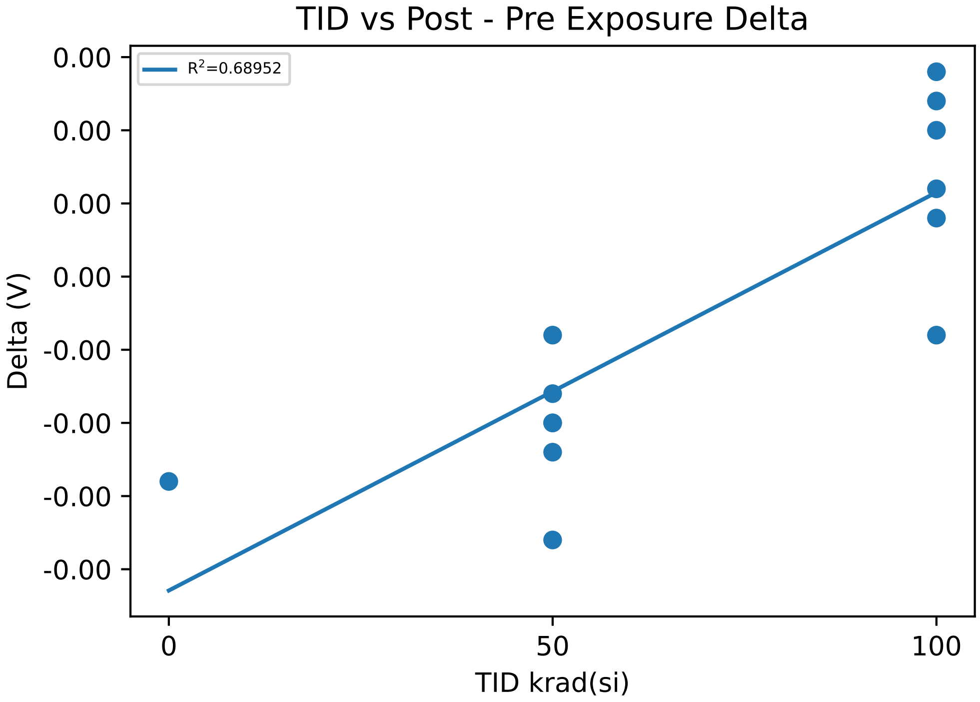
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.0682	0.0658	-0.0024
60	50	Biased	0.0685	0.0663	-0.0022
61	50	Biased	0.0685	0.0662	-0.0023
63	100	Biased	0.0681	0.0653	-0.0028
64	100	Biased	0.0688	0.0659	-0.0029
65	100	Biased	0.068	0.0652	-0.0028
66	50	Unbiased	0.0681	0.0665	-0.0016
67	50	Unbiased	0.0681	0.0664	-0.0017
68	50	Unbiased	0.068	0.0666	-0.0014
69	100	Unbiased	0.0684	0.0662	-0.0022
70	100	Unbiased	0.068	0.0657	-0.0023
71	100	Unbiased	0.0682	0.0658	-0.0024
72	0	Control	0.0679	0.0676	-0.0003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0679	0.0679	0.0679		0.0676	0.0676	0.0676		-0.0003	-0.0003	-0.0003	
50	0.068	0.068233	0.0685	0.00021602	0.0658	0.0663	0.0666	0.00028284	-0.0024	-0.0019333	-0.0014	0.00041793
100	0.068	0.06825	0.0688	0.00030822	0.0652	0.065683	0.0662	0.00037639	-0.0029	-0.0025667	-0.0022	0.00030111

Device Test: 47.2 VOH Delta LO VIN_14V





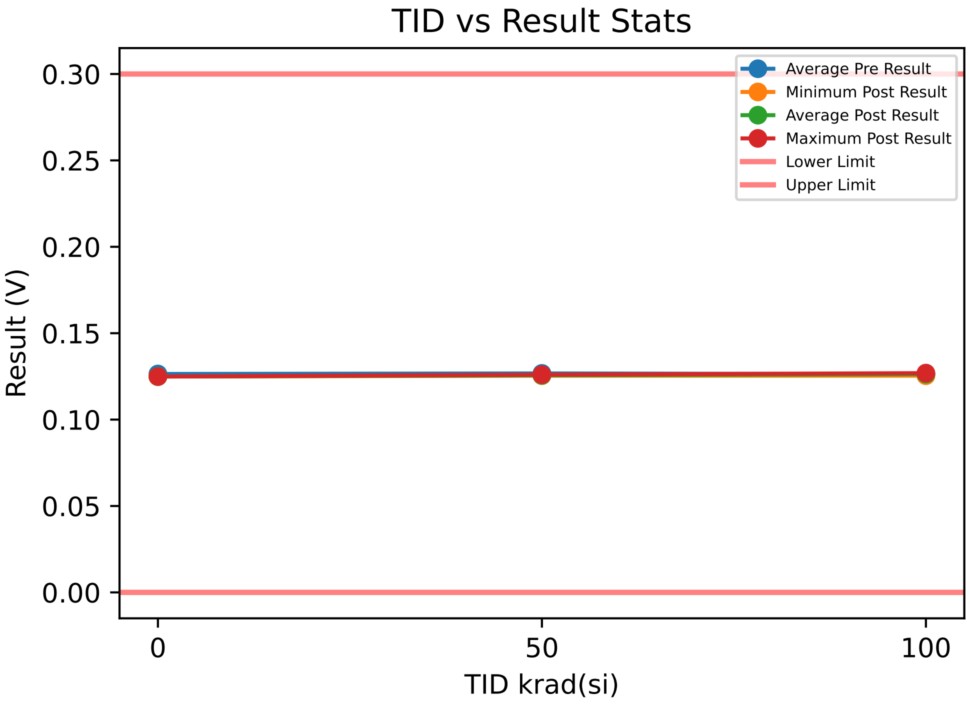
Test Results (Lower Limit = 0.0, Upper Limit = 0.3 (V))

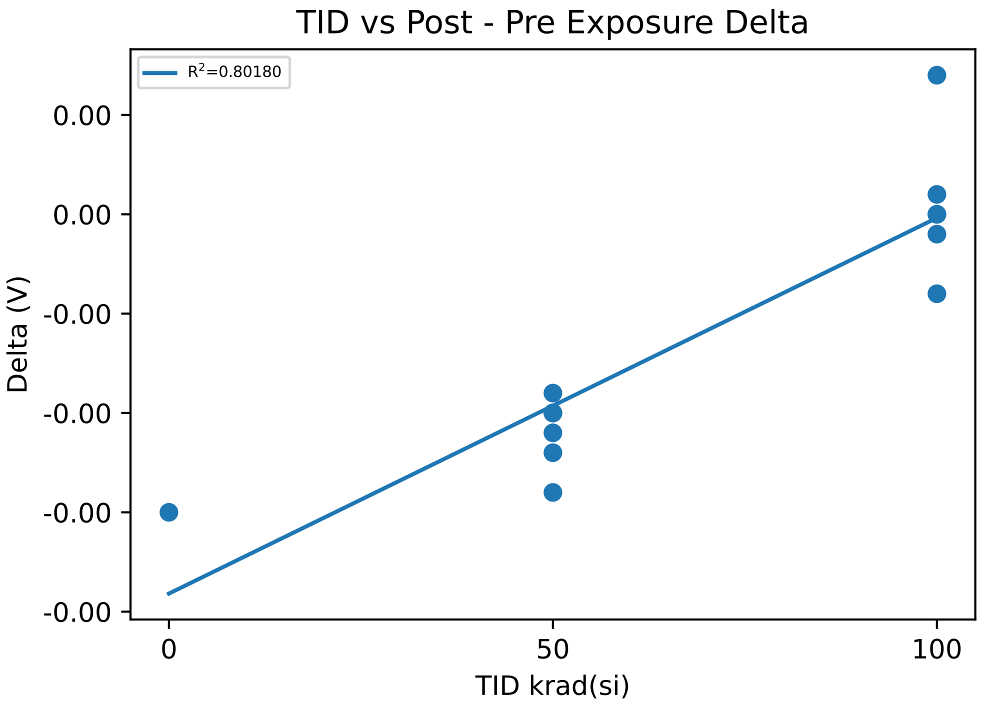
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.1254	0.1245	-0.0009
60	50	Biased	0.1257	0.1251	-0.0006
61	50	Biased	0.1254	0.1249	-0.0005
63	100	Biased	0.1252	0.1258	0.0006
64	100	Biased	0.1257	0.1262	0.0005
65	100	Biased	0.1259	0.1257	-0.0002
66	50	Unbiased	0.1259	0.1255	-0.0004
67	50	Unbiased	0.1267	0.1265	-0.0002
68	50	Unbiased	0.1258	0.1253	-0.0005
69	100	Unbiased	0.1263	0.1265	0.0002
70	100	Unbiased	0.1262	0.1265	0.0003
71	100	Unbiased	0.1268	0.1275	0.0007
72	0	Control	0.1259	0.1252	-0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1259	0.1259	0.1259		0.1252	0.1252	0.1252		-0.0007	-0.0007	-0.0007	
50	0.1254	0.12582	0.1267	0.00047924	0.1245	0.1253	0.1265	0.00068118	-0.0009	-0.00051667	-0.0002	0.00023166
100	0.1252	0.12602	0.1268	0.00054924	0.1257	0.12637	0.1275	0.00065013	-0.0002	0.00035	0.0007	0.00032711

Device Test: 47.3 VOH Delta HO VIN_14V





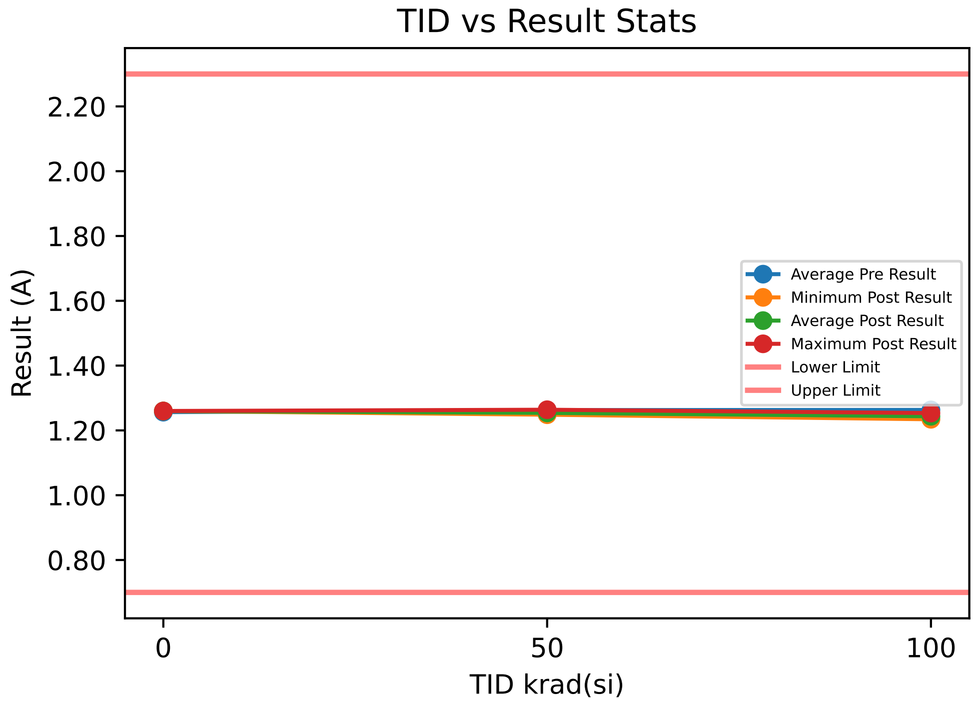
Test Results (Lower Limit = 0.0, Upper Limit = 0.3 (V))

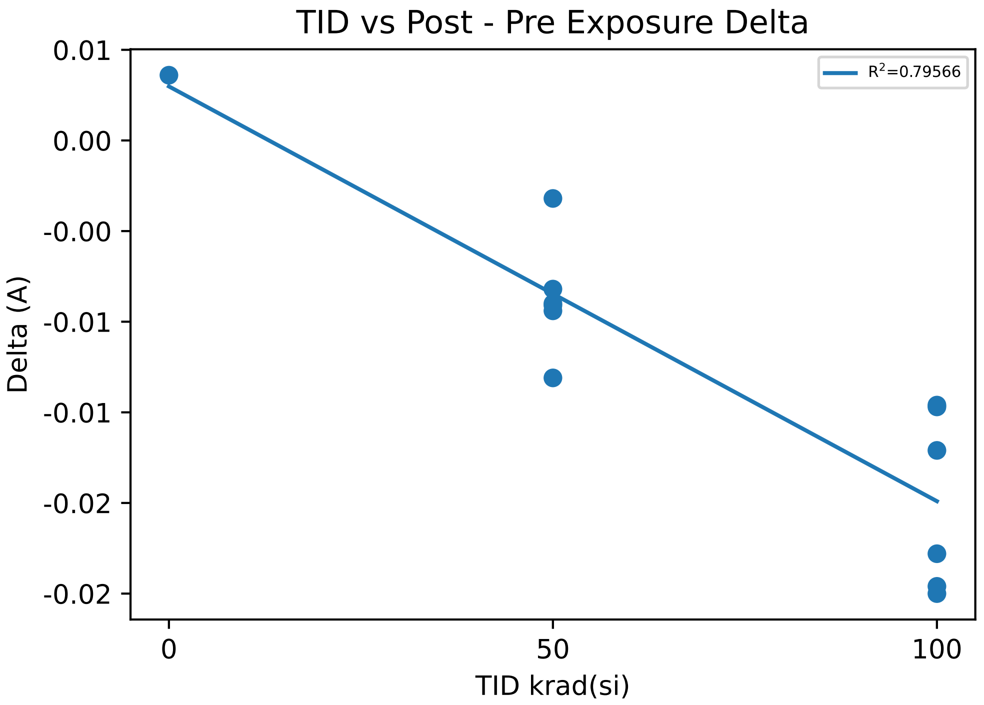
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.1264	0.1255	-0.0009
60	50	Biased	0.1274	0.126	-0.0014
61	50	Biased	0.1265	0.1254	-0.0011
63	100	Biased	0.1269	0.1268	-0.0001
64	100	Biased	0.1269	0.1269	0
65	100	Biased	0.1259	0.126	0.0001
66	50	Unbiased	0.1269	0.1257	-0.0012
67	50	Unbiased	0.1267	0.1257	-0.001
68	50	Unbiased	0.1265	0.1255	-0.001
69	100	Unbiased	0.126	0.1267	0.0007
70	100	Unbiased	0.1261	0.1261	0
71	100	Unbiased	0.1258	0.1254	-0.0004
72	0	Control	0.1264	0.1249	-0.0015

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1264	0.1264	0.1264		0.1249	0.1249	0.1249		-0.0015	-0.0015	-0.0015	
50	0.1264	0.12673	0.1274	0.00037238	0.1254	0.12563	0.126	0.00021602	-0.0014	-0.0011	-0.0009	0.00017889
100	0.1258	0.12627	0.1269	0.00050067	0.1254	0.12632	0.1269	0.00058452	-0.0004	5e-05	0.0007	0.00036194

Device Test: 50.0 IOH LO VIN_10V





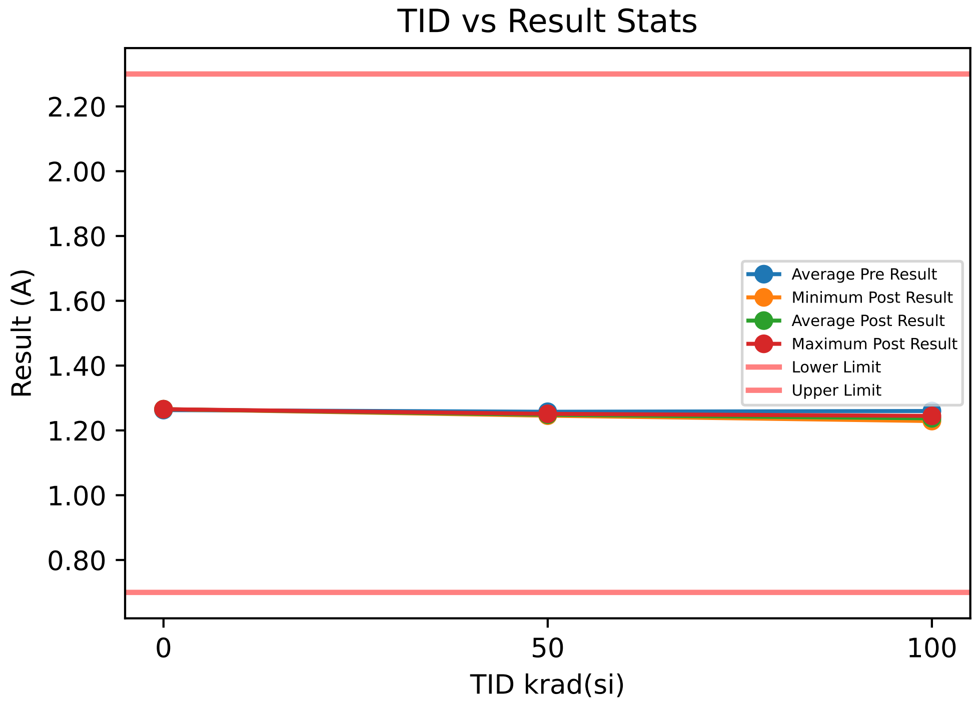
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

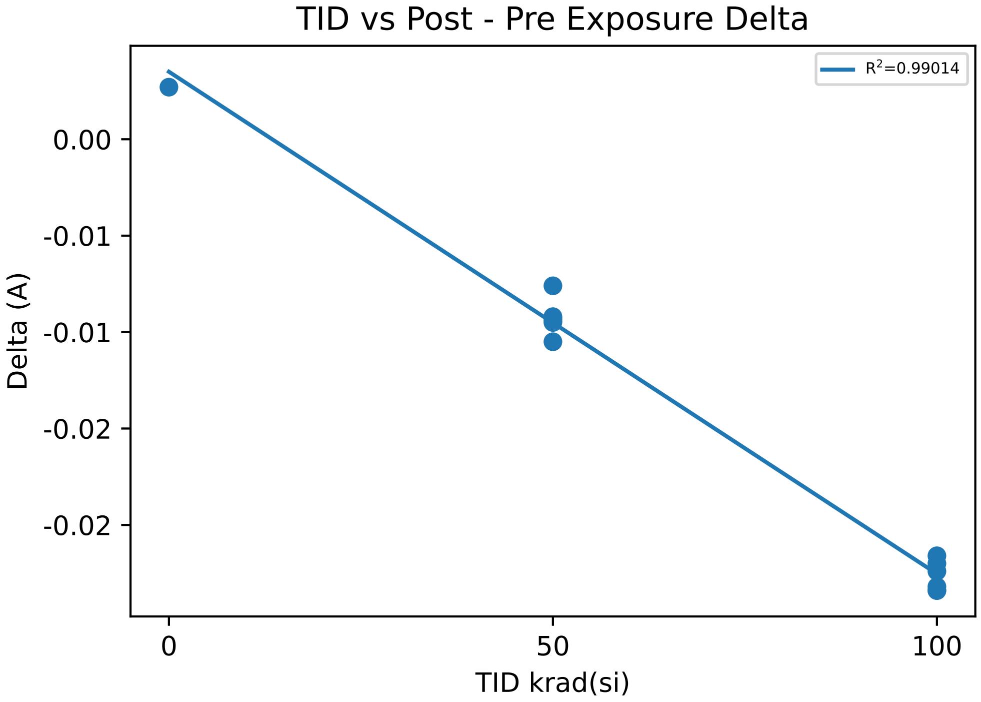
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.267	1.2638	-0.0032
60	50	Biased	1.2575	1.2493	-0.0082
61	50	Biased	1.2654	1.2563	-0.0091
63	100	Biased	1.2706	1.2535	-0.0171
64	100	Biased	1.2599	1.2452	-0.0147
65	100	Biased	1.267	1.2524	-0.0146
66	50	Unbiased	1.263	1.254	-0.009
67	50	Unbiased	1.2615	1.2484	-0.0131
68	50	Unbiased	1.2614	1.252	-0.0094
69	100	Unbiased	1.2635	1.2385	-0.025
70	100	Unbiased	1.2571	1.2343	-0.0228
71	100	Unbiased	1.2615	1.2369	-0.0246
72	0	Control	1.2563	1.2599	0.0036

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2563	1.2563	1.2563		1.2599	1.2599	1.2599		0.0036	0.0036	0.0036	
50	1.2575	1.2626	1.267	0.003347	1.2484	1.254	1.2638	0.0056351	-0.0131	-0.0086667	-0.0032	0.003181
100	1.2571	1.2633	1.2706	0.0049041	1.2343	1.2435	1.2535	0.0081889	-0.025	-0.0198	-0.0146	0.0048871

Device Test: 50.1 IOH HO VIN_10V





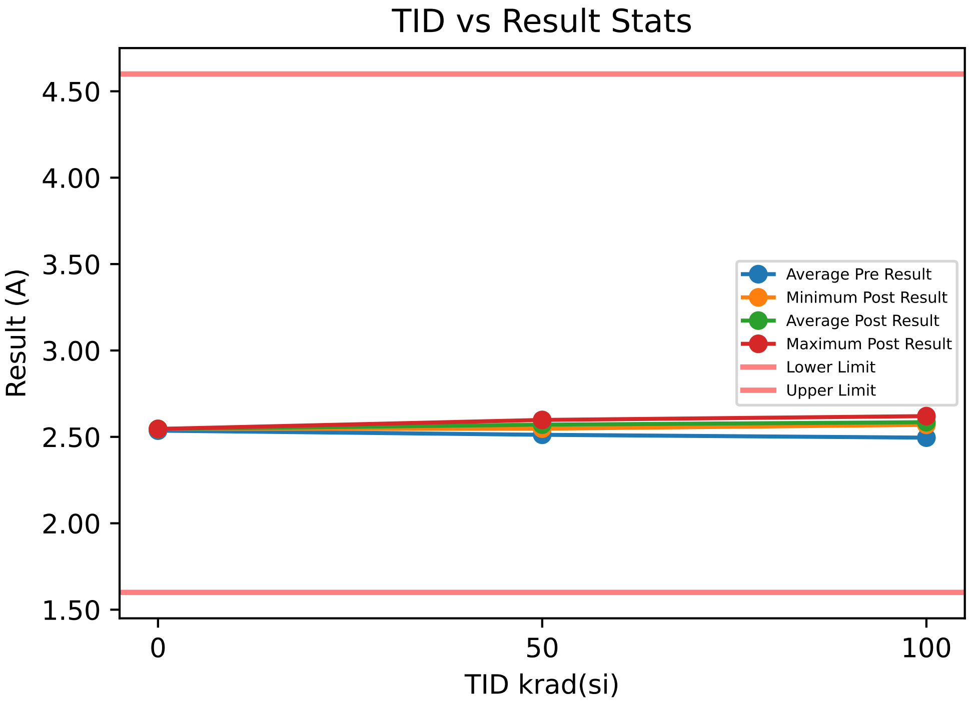
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

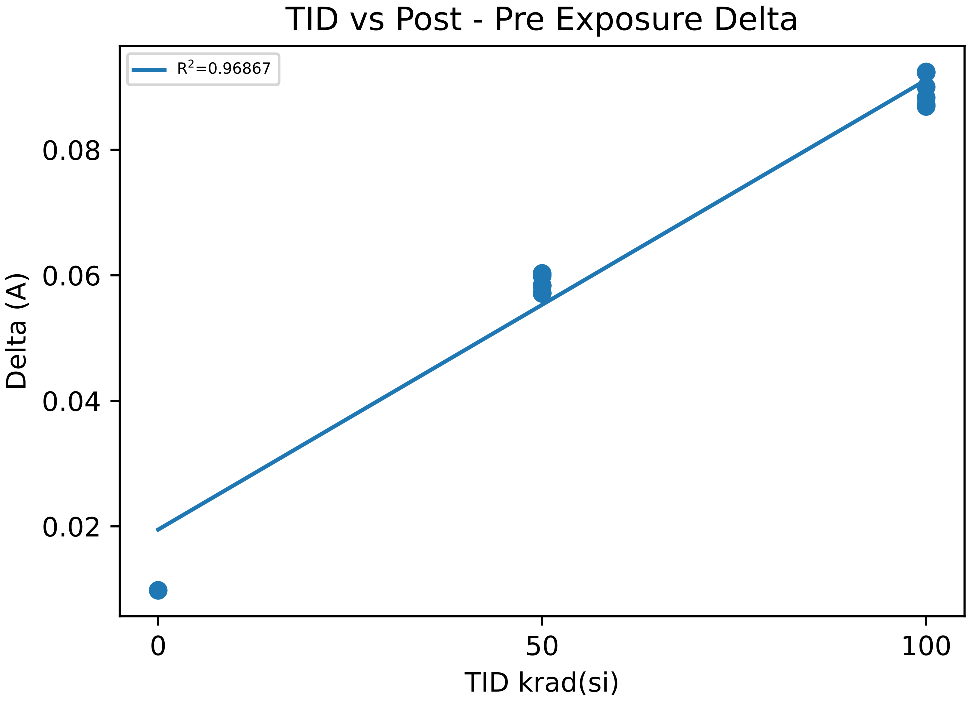
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.2583	1.249	-0.0093
60	50	Biased	1.254	1.2464	-0.0076
61	50	Biased	1.2548	1.2454	-0.0094
63	100	Biased	1.2512	1.2288	-0.0224
64	100	Biased	1.2548	1.2328	-0.022
65	100	Biased	1.2599	1.2365	-0.0234
66	50	Unbiased	1.2603	1.2511	-0.0092
67	50	Unbiased	1.2587	1.2482	-0.0105
68	50	Unbiased	1.2591	1.2496	-0.0095
69	100	Unbiased	1.2619	1.2403	-0.0216
70	100	Unbiased	1.2682	1.2448	-0.0234
71	100	Unbiased	1.2631	1.2399	-0.0232
72	0	Control	1.2627	1.2654	0.0027

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2627	1.2627	1.2627		1.2654	1.2654	1.2654		0.0027	0.0027	0.0027	
50	1.254	1.2575	1.2603	0.0025303	1.2454	1.2483	1.2511	0.0020999	-0.0105	-0.00925	-0.0076	0.00093541
100	1.2512	1.2598	1.2682	0.0060797	1.2288	1.2372	1.2448	0.0057458	-0.0234	-0.022667	-0.0216	0.00077632

Device Test: 50.2 IOL LO VIN_10V





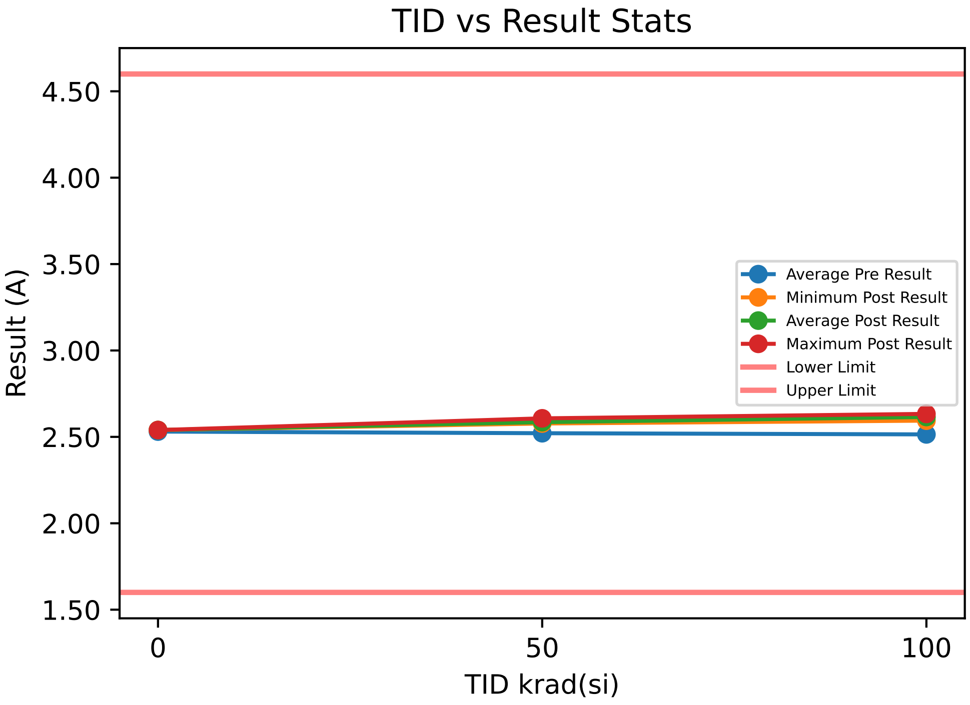
Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

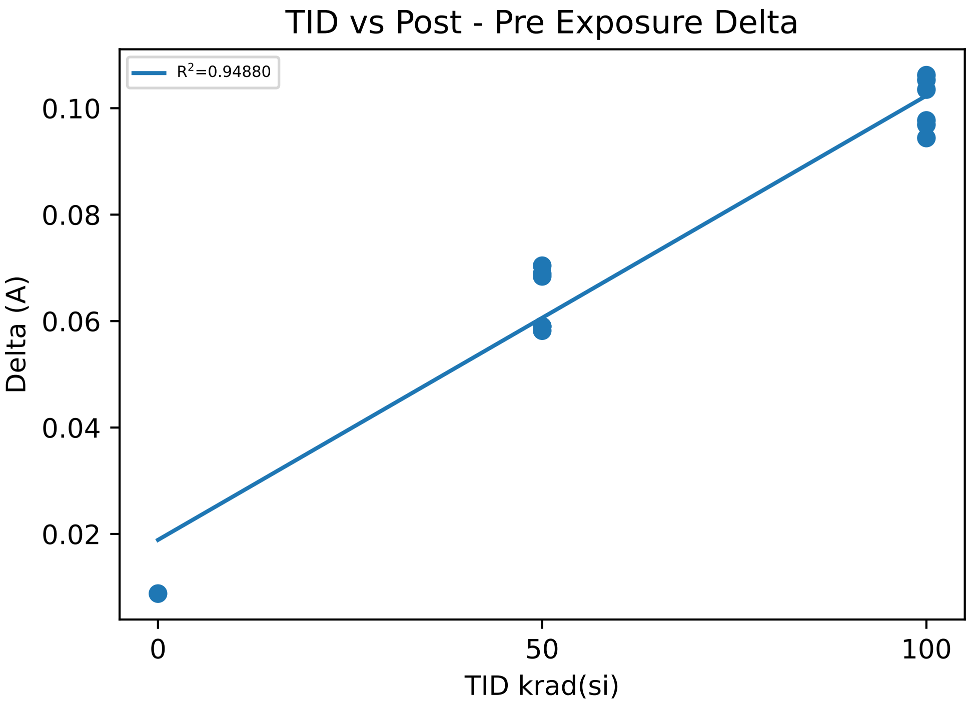
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.5302	2.5905	0.0603
60	50	Biased	2.5314	2.5885	0.0571
61	50	Biased	2.5381	2.598	0.0599
63	100	Biased	2.5092	2.5964	0.0872
64	100	Biased	2.5318	2.6201	0.0883
65	100	Biased	2.491	2.5779	0.0869
66	50	Unbiased	2.4891	2.5475	0.0584
67	50	Unbiased	2.4918	2.549	0.0572
68	50	Unbiased	2.4919	2.5502	0.0583
69	100	Unbiased	2.4843	2.5767	0.0924
70	100	Unbiased	2.4773	2.5696	0.0923
71	100	Unbiased	2.4796	2.5696	0.09
72	0	Control	2.5361	2.5459	0.0098

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5361	2.5361	2.5361		2.5459	2.5459	2.5459		0.0098	0.0098	0.0098	
50	2.4891	2.5121	2.5381	0.023346	2.5475	2.5706	2.598	0.024015	0.0571	0.058533	0.0603	0.0013337
100	2.4773	2.4955	2.5318	0.021143	2.5696	2.5851	2.6201	0.019777	0.0869	0.089517	0.0924	0.002449

Device Test: 50.3 IOL HO VIN_10V





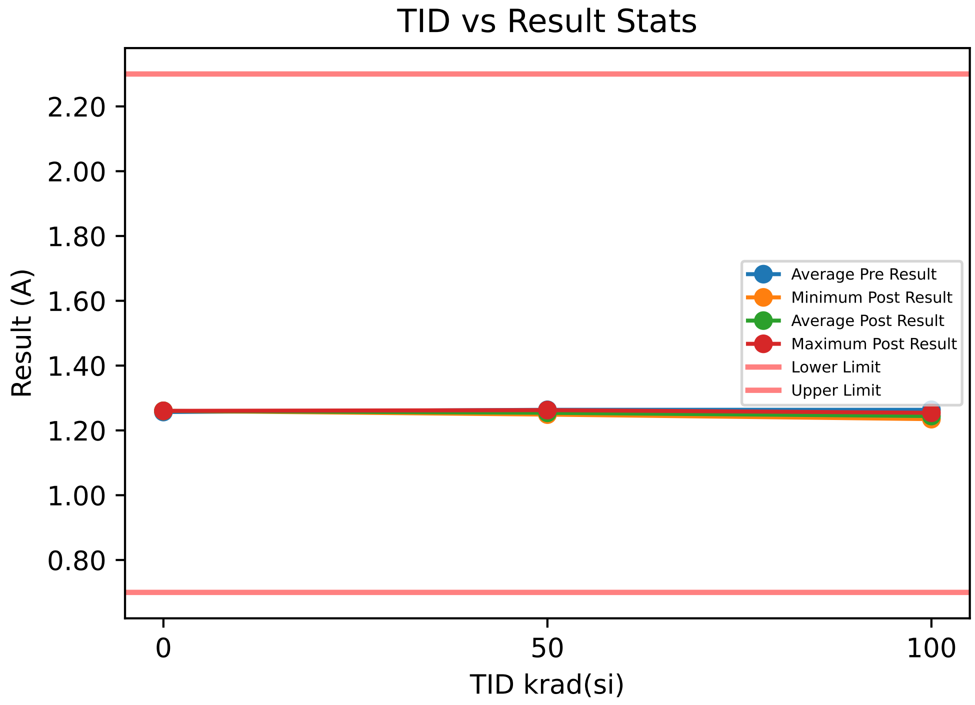
Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

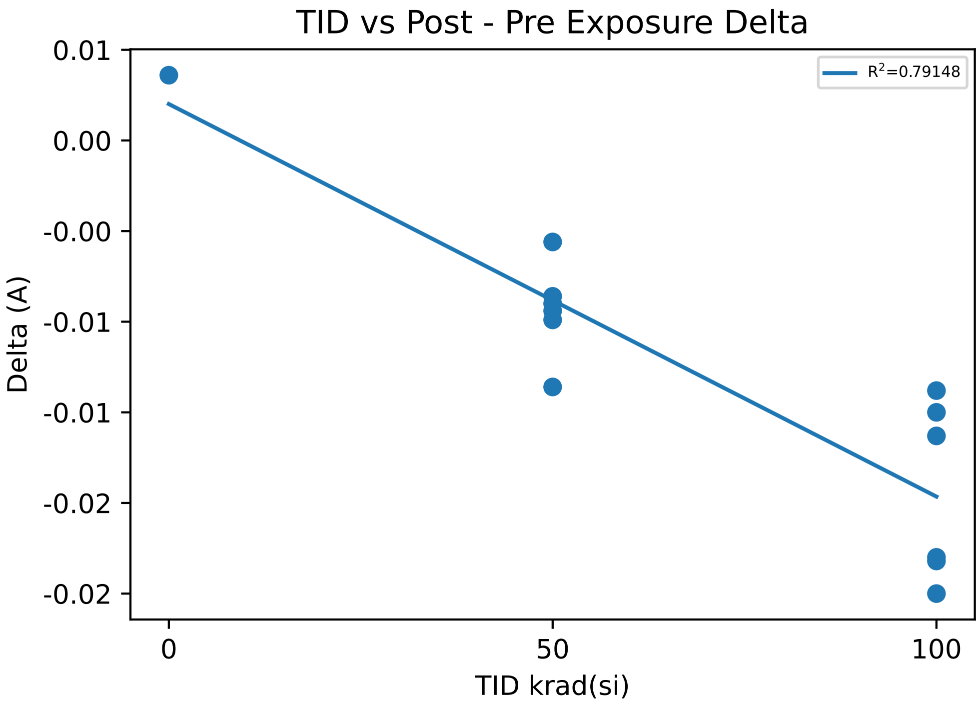
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.5369	2.6073	0.0704
60	50	Biased	2.5085	2.5774	0.0689
61	50	Biased	2.514	2.5824	0.0684
63	100	Biased	2.5203	2.6238	0.1035
64	100	Biased	2.4971	2.6033	0.1062
65	100	Biased	2.5211	2.6264	0.1053
66	50	Unbiased	2.522	2.581	0.059
67	50	Unbiased	2.5223	2.5805	0.0582
68	50	Unbiased	2.5236	2.5826	0.059
69	100	Unbiased	2.497	2.5939	0.0969
70	100	Unbiased	2.5354	2.6331	0.0977
71	100	Unbiased	2.5156	2.61	0.0944
72	0	Control	2.5307	2.5395	0.0088

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5307	2.5307	2.5307		2.5395	2.5395	2.5395		0.0088	0.0088	0.0088	
50	2.5085	2.5212	2.5369	0.0096667	2.5774	2.5852	2.6073	0.010987	0.0582	0.063983	0.0704	0.005796
100	2.497	2.5144	2.5354	0.014995	2.5939	2.6151	2.6331	0.015113	0.0944	0.10067	0.1062	0.0049472

Device Test: 51.0 IOH LO VIN_12V





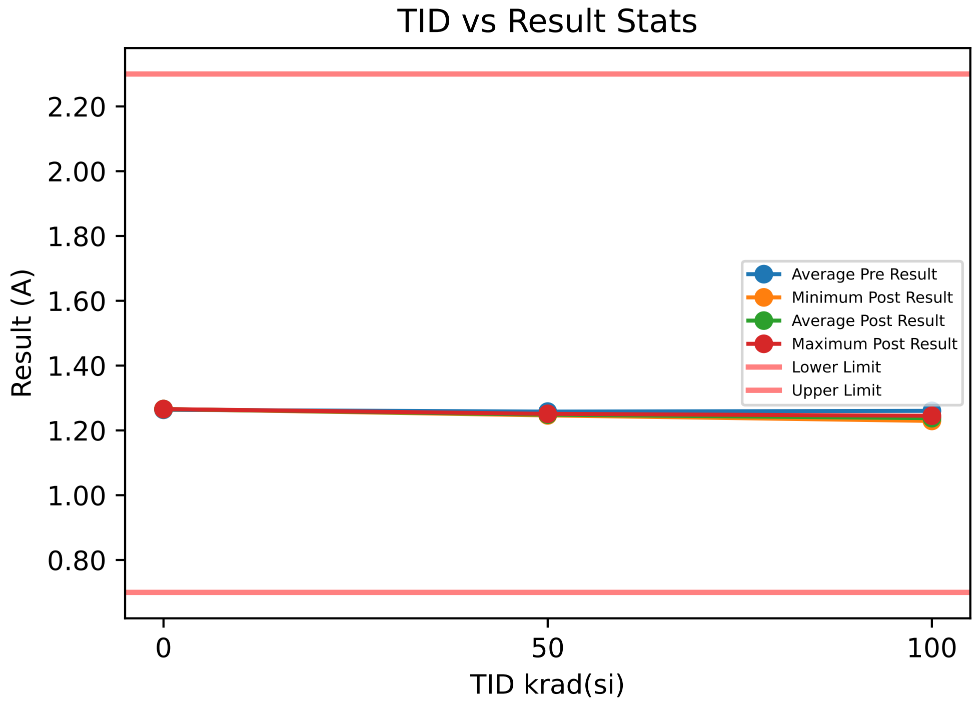
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

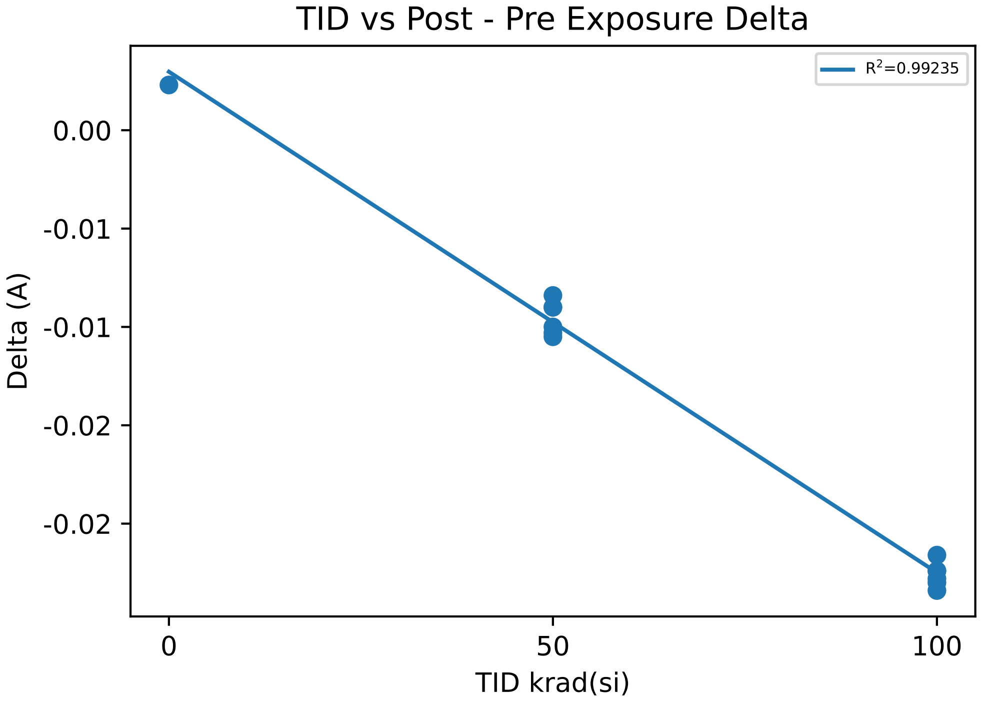
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.2682	1.2626	-0.0056
60	50	Biased	1.2587	1.2497	-0.009
61	50	Biased	1.2666	1.2567	-0.0099
63	100	Biased	1.2706	1.2543	-0.0163
64	100	Biased	1.2606	1.2468	-0.0138
65	100	Biased	1.2678	1.2528	-0.015
66	50	Unbiased	1.2634	1.2548	-0.0086
67	50	Unbiased	1.2623	1.2487	-0.0136
68	50	Unbiased	1.2622	1.2528	-0.0094
69	100	Unbiased	1.2639	1.2389	-0.025
70	100	Unbiased	1.2579	1.2347	-0.0232
71	100	Unbiased	1.2611	1.2381	-0.023
72	0	Control	1.2567	1.2603	0.0036

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2567	1.2567	1.2567		1.2603	1.2603	1.2603		0.0036	0.0036	0.0036	
50	1.2587	1.2636	1.2682	0.0034016	1.2487	1.2542	1.2626	0.0050917	-0.0136	-0.00935	-0.0056	0.0025735
100	1.2579	1.2636	1.2706	0.0047845	1.2347	1.2443	1.2543	0.008225	-0.025	-0.019383	-0.0138	0.0048803

Device Test: 51.1 IOH HO VIN_12V





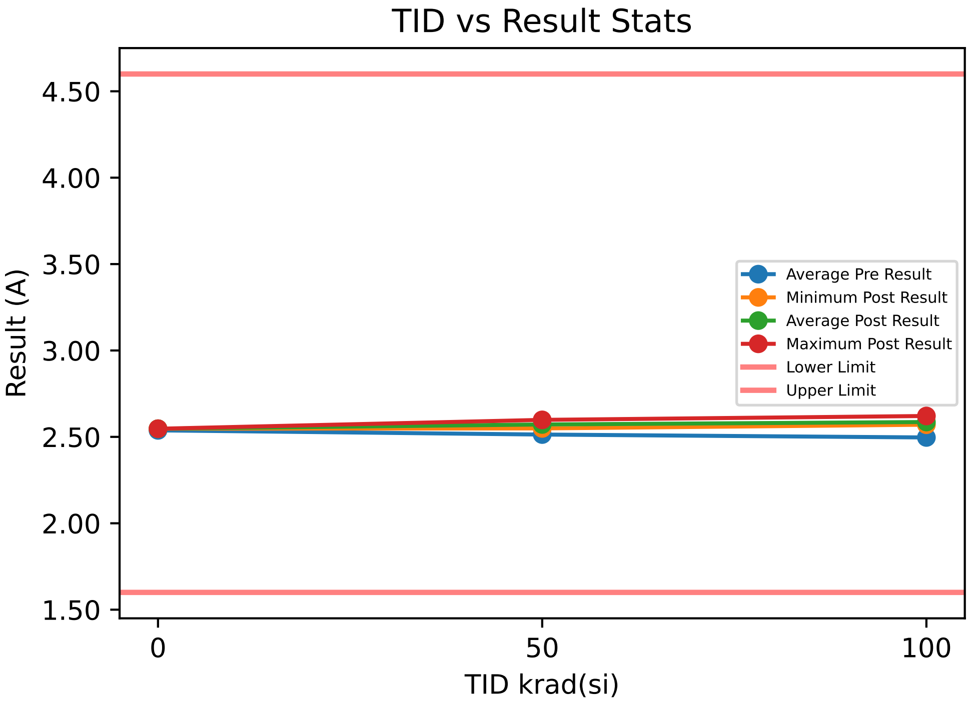
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

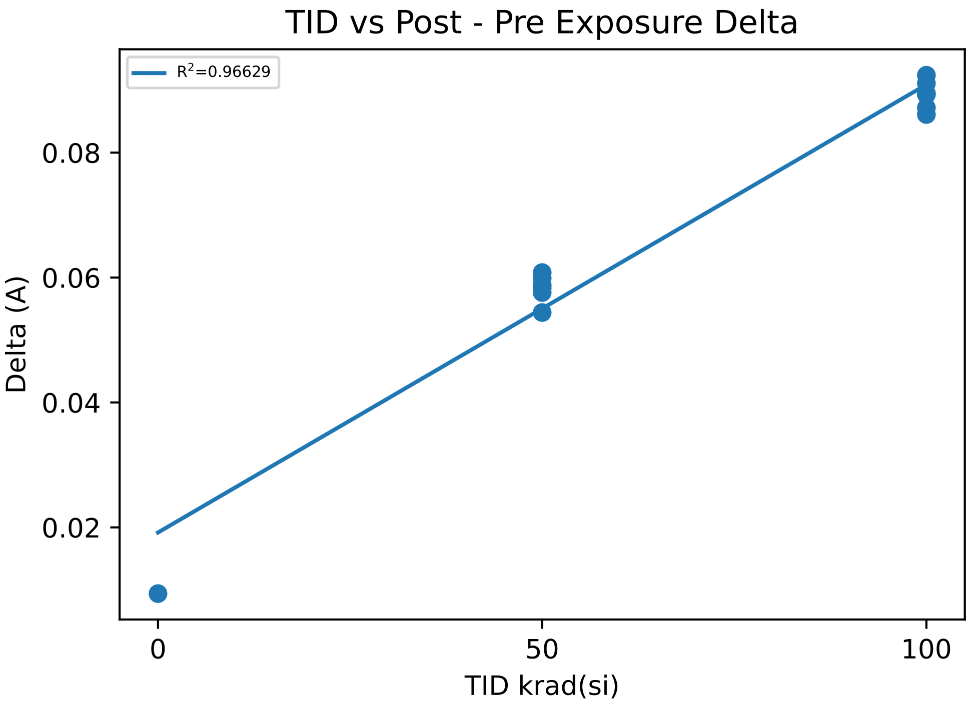
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.2583	1.2493	-0.009
60	50	Biased	1.2548	1.2464	-0.0084
61	50	Biased	1.2552	1.2462	-0.009
63	100	Biased	1.2516	1.2292	-0.0224
64	100	Biased	1.2556	1.2332	-0.0224
65	100	Biased	1.2603	1.2373	-0.023
66	50	Unbiased	1.2611	1.2511	-0.01
67	50	Unbiased	1.2591	1.2486	-0.0105
68	50	Unbiased	1.2599	1.2496	-0.0103
69	100	Unbiased	1.2623	1.2407	-0.0216
70	100	Unbiased	1.2686	1.2452	-0.0234
71	100	Unbiased	1.2635	1.2407	-0.0228
72	0	Control	1.2635	1.2658	0.0023

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2635	1.2635	1.2635		1.2658	1.2658	1.2658		0.0023	0.0023	0.0023	
50	1.2548	1.2581	1.2611	0.0025524	1.2462	1.2485	1.2511	0.0019138	-0.0105	-0.0095333	-0.0084	0.00084774
100	1.2516	1.2603	1.2686	0.0060151	1.2292	1.2377	1.2452	0.0057777	-0.0234	-0.0226	-0.0216	0.00061968

Device Test: 51.2 IOL LO VIN_12V





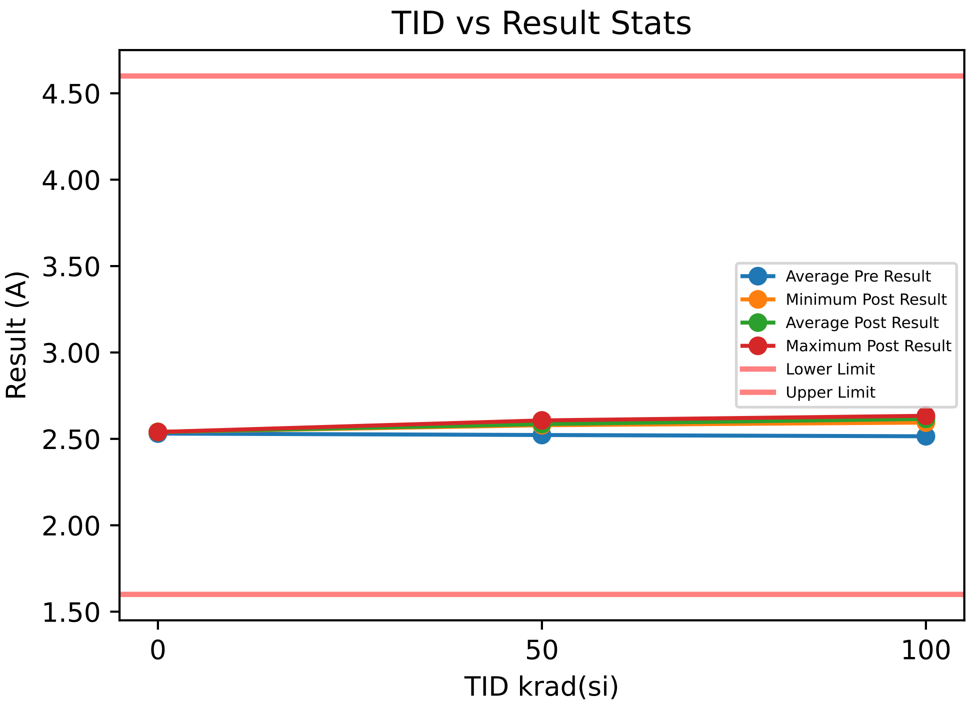
Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

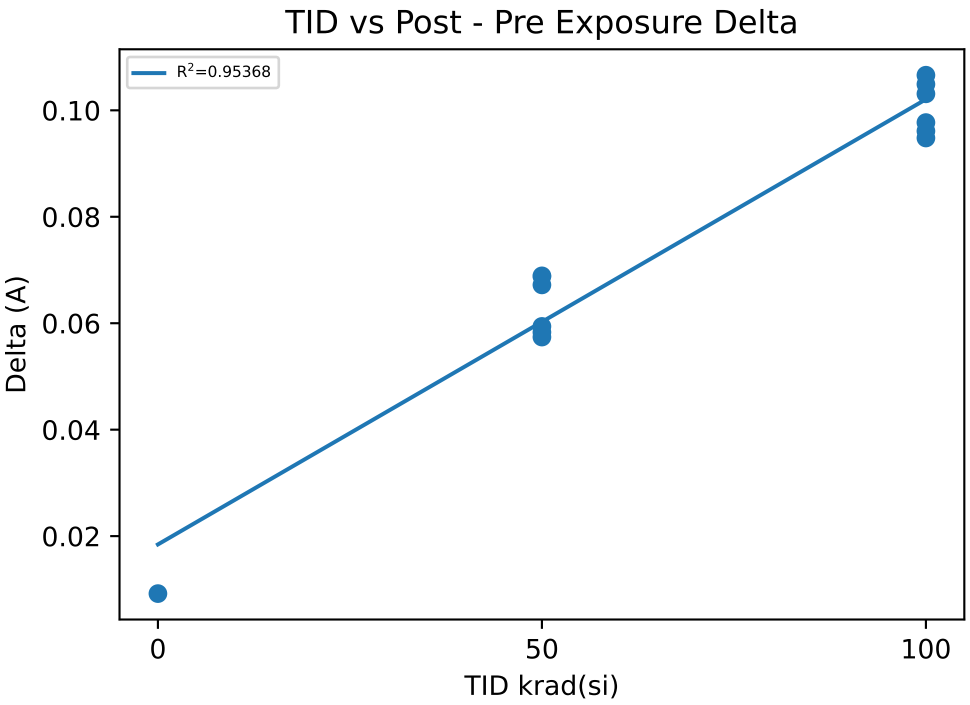
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.5313	2.5921	0.0608
60	50	Biased	2.5294	2.5893	0.0599
61	50	Biased	2.5396	2.5984	0.0588
63	100	Biased	2.5104	2.5976	0.0872
64	100	Biased	2.5314	2.6209	0.0895
65	100	Biased	2.4922	2.5783	0.0861
66	50	Unbiased	2.4907	2.549	0.0583
67	50	Unbiased	2.493	2.5506	0.0576
68	50	Unbiased	2.497	2.5514	0.0544
69	100	Unbiased	2.4855	2.5779	0.0924
70	100	Unbiased	2.4793	2.5704	0.0911
71	100	Unbiased	2.4811	2.5704	0.0893
72	0	Control	2.5377	2.5471	0.0094

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5377	2.5377	2.5377		2.5471	2.5471	2.5471		0.0094	0.0094	0.0094	
50	2.4907	2.5135	2.5396	0.022195	2.549	2.5718	2.5984	0.023712	0.0544	0.0583	0.0608	0.0022253
100	2.4793	2.4967	2.5314	0.020414	2.5704	2.5859	2.6209	0.01982	0.0861	0.089267	0.0924	0.0023466

Device Test: 51.3 IOL HO VIN_12V





Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

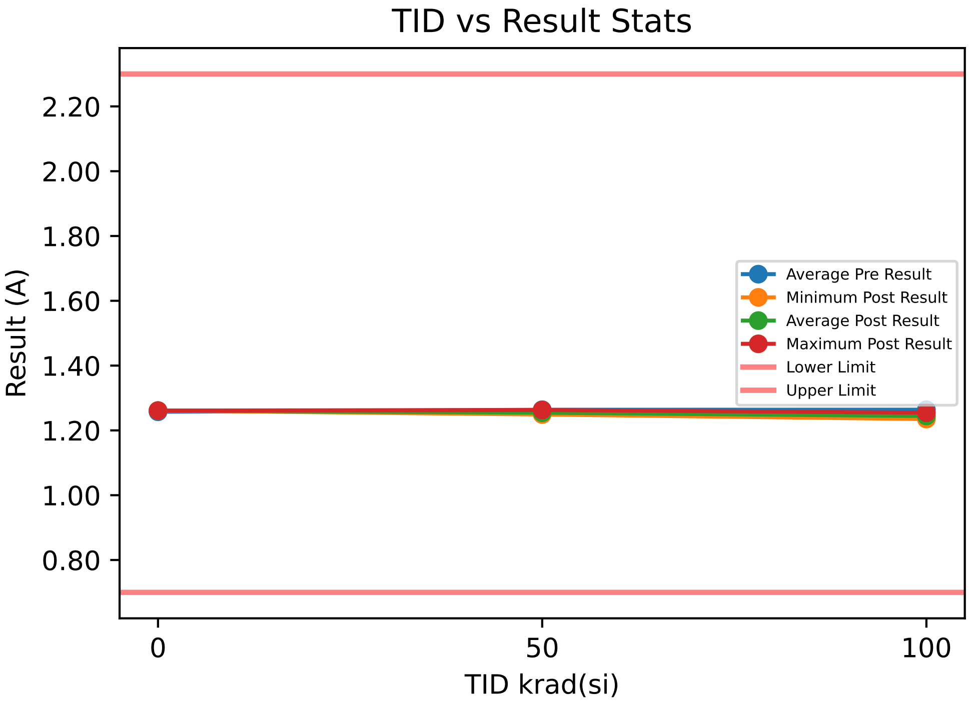
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.5381	2.6069	0.0688
60	50	Biased	2.5101	2.579	0.0689
61	50	Biased	2.5152	2.5824	0.0672
63	100	Biased	2.5211	2.6242	0.1031
64	100	Biased	2.4971	2.6037	0.1066
65	100	Biased	2.5219	2.6268	0.1049
66	50	Unbiased	2.5228	2.5822	0.0594
67	50	Unbiased	2.5235	2.5809	0.0574
68	50	Unbiased	2.5247	2.583	0.0583
69	100	Unbiased	2.4982	2.5943	0.0961
70	100	Unbiased	2.5358	2.6335	0.0977
71	100	Unbiased	2.516	2.6108	0.0948
72	0	Control	2.5307	2.5399	0.0092

Test Statistics (A)

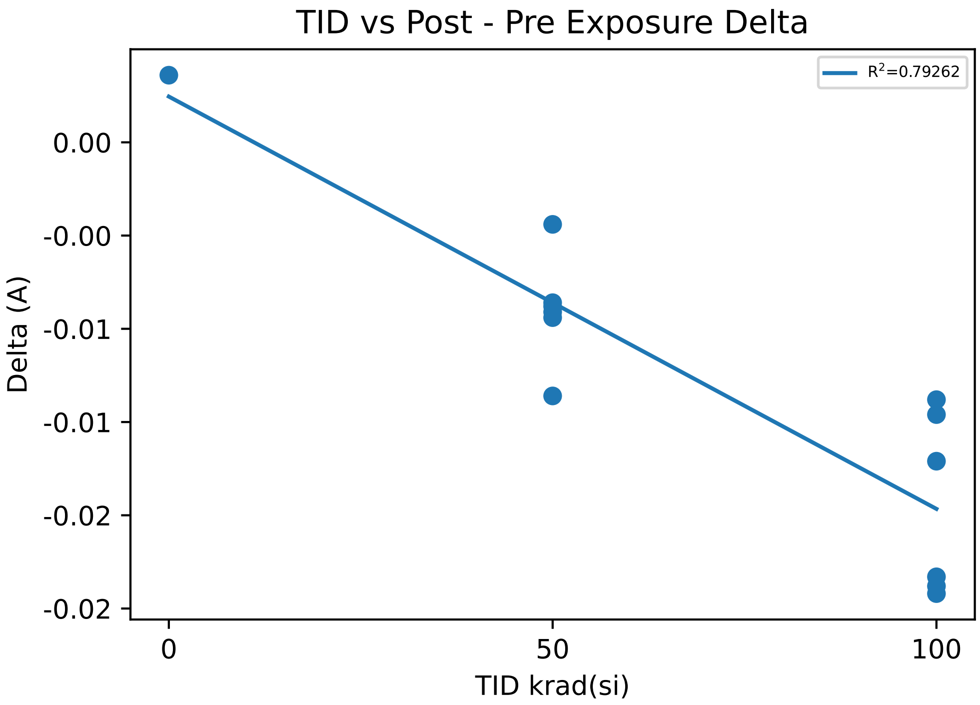
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5307	2.5307	2.5307		2.5399	2.5399	2.5399		0.0092	0.0092	0.0092	
50	2.5101	2.5224	2.5381	0.0095528	2.579	2.5857	2.6069	0.010467	0.0574	0.063333	0.0689	0.0055106
100	2.4971	2.515	2.5358	0.014974	2.5943	2.6156	2.6335	0.015087	0.0948	0.10053	0.1066	0.0049601

Device Test: 52.0 IOH LO VIN_14V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



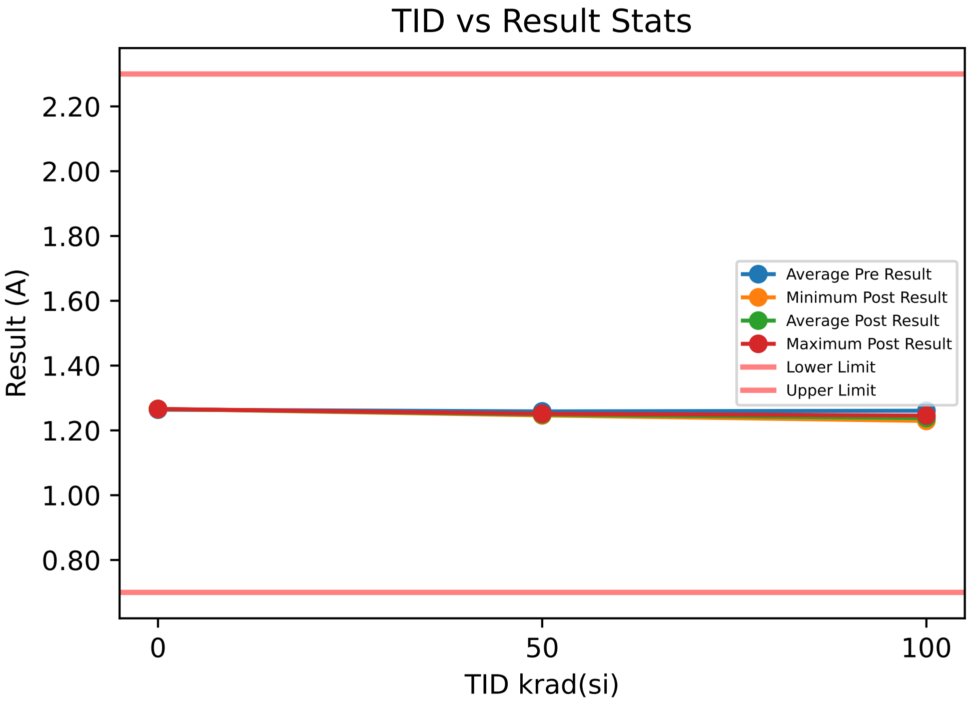
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

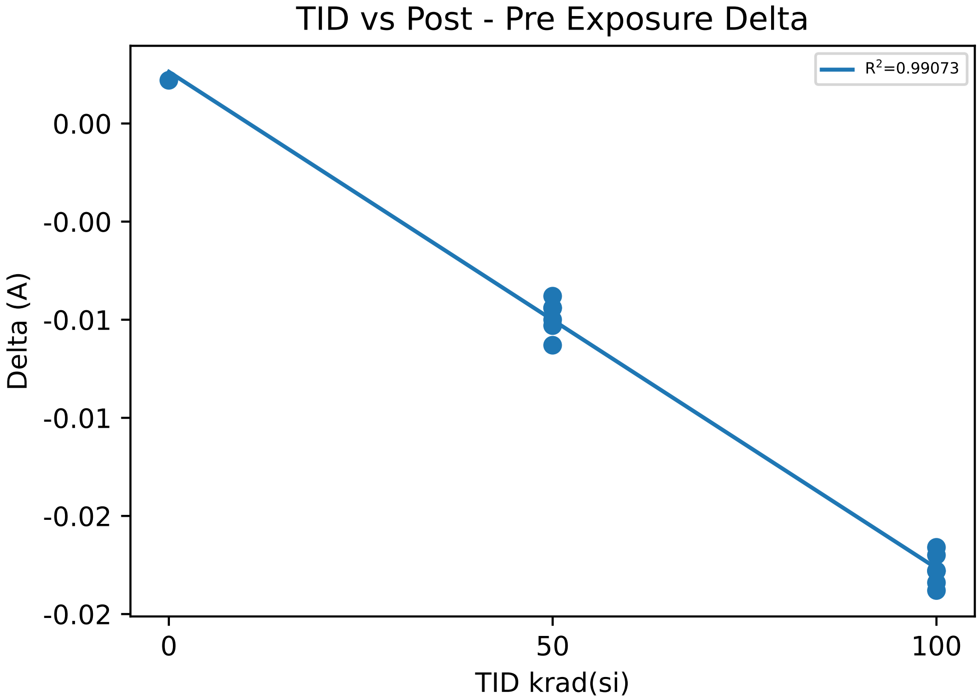
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.2674	1.263	-0.0044
60	50	Biased	1.2591	1.25	-0.0091
61	50	Biased	1.2666	1.2578	-0.0088
63	100	Biased	1.2718	1.2547	-0.0171
64	100	Biased	1.261	1.2472	-0.0138
65	100	Biased	1.2678	1.2532	-0.0146
66	50	Unbiased	1.2642	1.2548	-0.0094
67	50	Unbiased	1.2627	1.2491	-0.0136
68	50	Unbiased	1.2622	1.2536	-0.0086
69	100	Unbiased	1.2627	1.2385	-0.0242
70	100	Unbiased	1.2583	1.235	-0.0233
71	100	Unbiased	1.2619	1.2381	-0.0238
72	0	Control	1.2575	1.2611	0.0036

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2575	1.2575	1.2575		1.2611	1.2611	1.2611		0.0036	0.0036	0.0036	
50	1.2591	1.2637	1.2674	0.0030581	1.2491	1.2547	1.263	0.0051608	-0.0136	-0.0089833	-0.0044	0.0029219
100	1.2583	1.2639	1.2718	0.0049564	1.235	1.2445	1.2547	0.0084168	-0.0242	-0.019467	-0.0138	0.004843

Device Test: 52.1 IOH HO VIN_14V





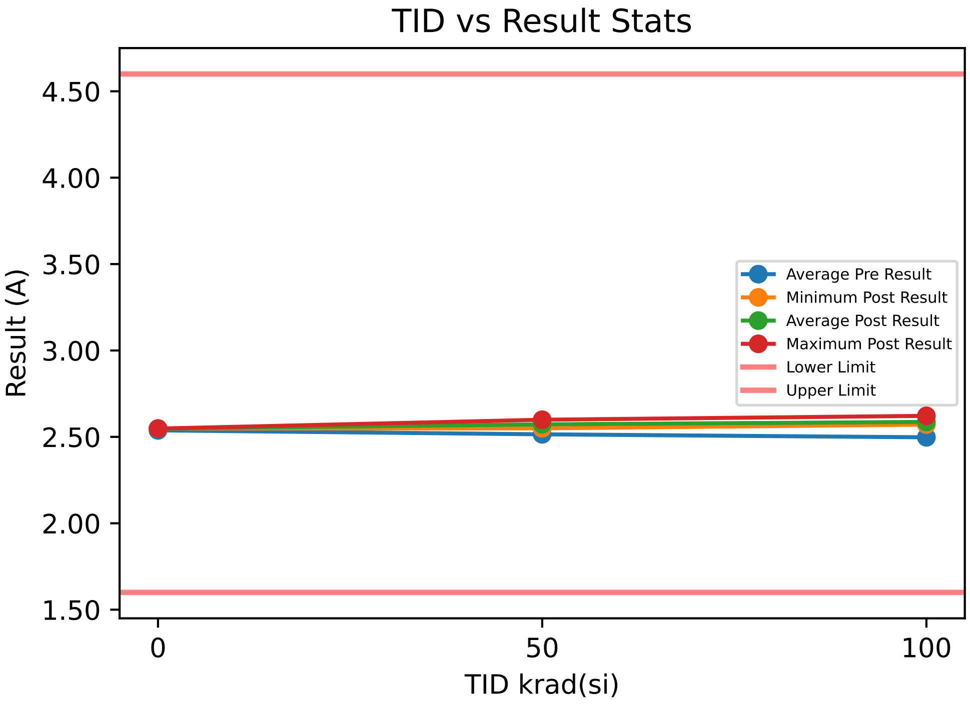
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

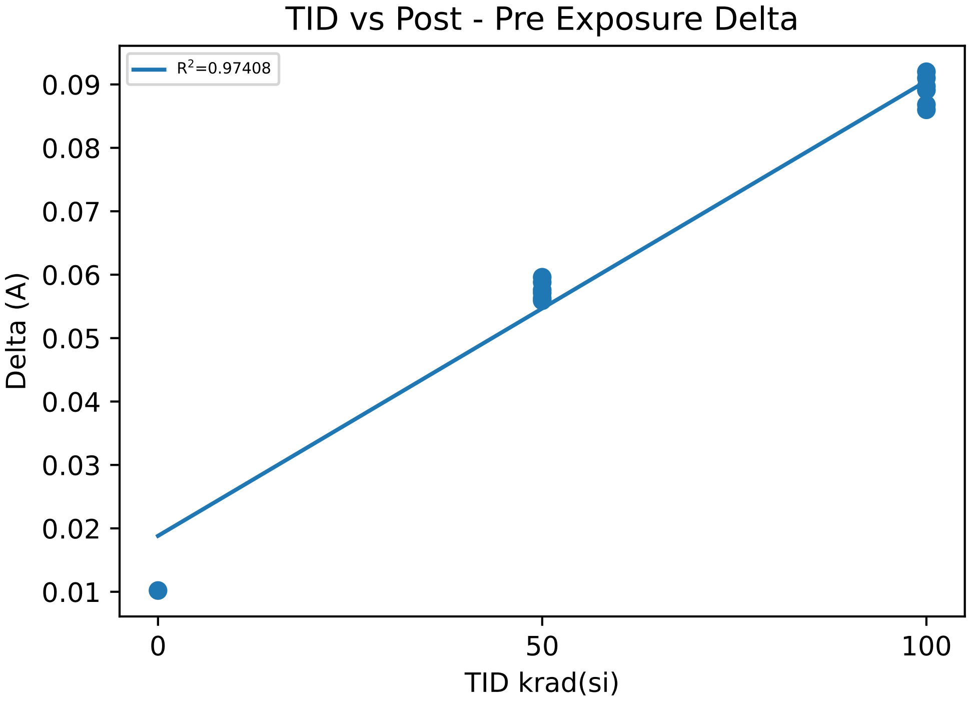
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.2591	1.2497	-0.0094
60	50	Biased	1.2556	1.2468	-0.0088
61	50	Biased	1.2556	1.2462	-0.0094
63	100	Biased	1.252	1.2292	-0.0228
64	100	Biased	1.2556	1.234	-0.0216
65	100	Biased	1.2607	1.2373	-0.0234
66	50	Unbiased	1.2615	1.2515	-0.01
67	50	Unbiased	1.2599	1.2486	-0.0113
68	50	Unbiased	1.2603	1.25	-0.0103
69	100	Unbiased	1.2631	1.2411	-0.022
70	100	Unbiased	1.2694	1.2456	-0.0238
71	100	Unbiased	1.2635	1.2407	-0.0228
72	0	Control	1.2639	1.2661	0.0022

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2639	1.2639	1.2639		1.2661	1.2661	1.2661		0.0022	0.0022	0.0022	
50	1.2556	1.2587	1.2615	0.0024985	1.2462	1.2488	1.2515	0.0020169	-0.0113	-0.0098667	-0.0088	0.0008756
100	1.252	1.2607	1.2694	0.0061804	1.2292	1.238	1.2456	0.0058067	-0.0238	-0.022733	-0.0216	0.00082624

Device Test: 52.2 IOL LO VIN_14V





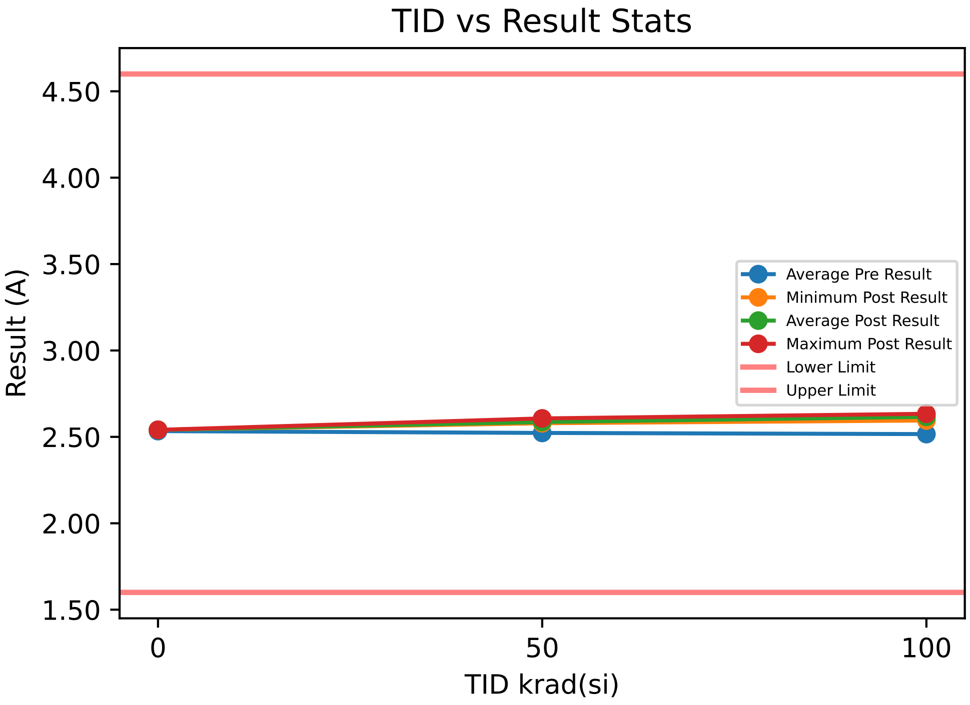
Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

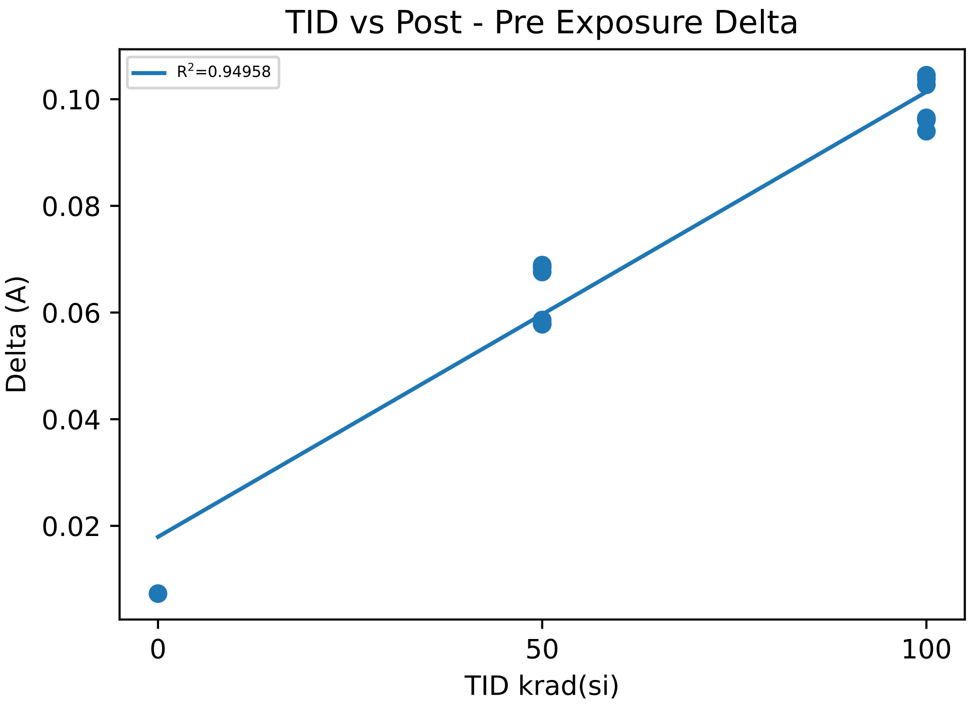
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.5325	2.5921	0.0596
60	50	Biased	2.533	2.5901	0.0571
61	50	Biased	2.5404	2.5992	0.0588
63	100	Biased	2.5112	2.598	0.0868
64	100	Biased	2.5326	2.6217	0.0891
65	100	Biased	2.4934	2.5794	0.086
66	50	Unbiased	2.4935	2.5494	0.0559
67	50	Unbiased	2.4938	2.5514	0.0576
68	50	Unbiased	2.4959	2.5522	0.0563
69	100	Unbiased	2.4863	2.5783	0.092
70	100	Unbiased	2.4801	2.5711	0.091
71	100	Unbiased	2.4815	2.5712	0.0897
72	0	Control	2.5377	2.5479	0.0102

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5377	2.5377	2.5377		2.5479	2.5479	2.5479		0.0102	0.0102	0.0102	
50	2.4935	2.5149	2.5404	0.022591	2.5494	2.5724	2.5992	0.023654	0.0559	0.05755	0.0596	0.0014321
100	2.4801	2.4975	2.5326	0.020595	2.5711	2.5866	2.6217	0.0198	0.086	0.0891	0.092	0.0023358

Device Test: 52.3 IOL HO VIN_14V





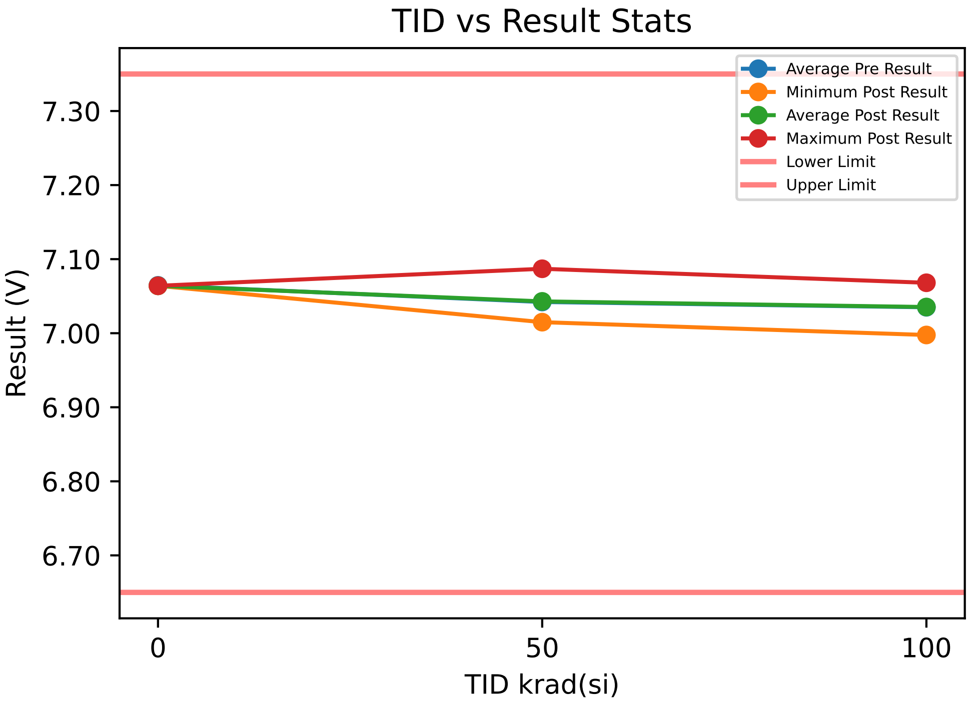
Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

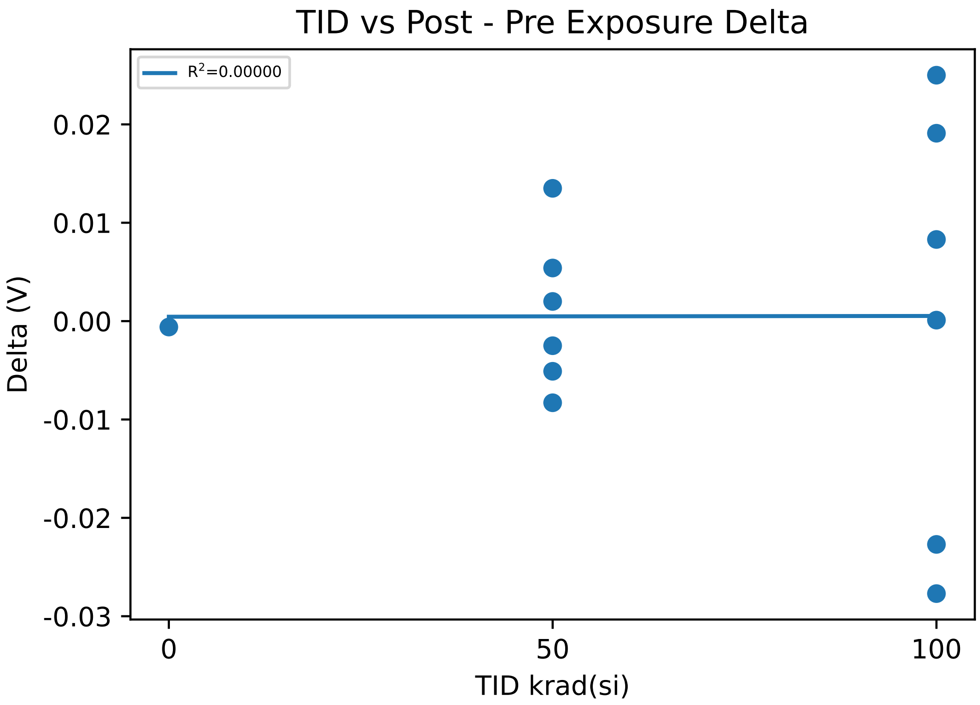
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.5385	2.6069	0.0684
60	50	Biased	2.5101	2.579	0.0689
61	50	Biased	2.5156	2.5832	0.0676
63	100	Biased	2.5219	2.6246	0.1027
64	100	Biased	2.4995	2.6033	0.1038
65	100	Biased	2.5227	2.6272	0.1045
66	50	Unbiased	2.5236	2.5822	0.0586
67	50	Unbiased	2.5239	2.5817	0.0578
68	50	Unbiased	2.5255	2.5834	0.0579
69	100	Unbiased	2.4986	2.5947	0.0961
70	100	Unbiased	2.537	2.6335	0.0965
71	100	Unbiased	2.5172	2.6112	0.094
72	0	Control	2.5334	2.5407	0.0073

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5334	2.5334	2.5334		2.5407	2.5407	2.5407		0.0073	0.0073	0.0073	
50	2.5101	2.5229	2.5385	0.0096823	2.579	2.5861	2.6069	0.010328	0.0578	0.0632	0.0689	0.0056089
100	2.4986	2.5162	2.537	0.014812	2.5947	2.6158	2.6335	0.015121	0.094	0.0996	0.1045	0.0045712

Device Test: 60.0 V_BP7L PWM 500kHz VIN_10V





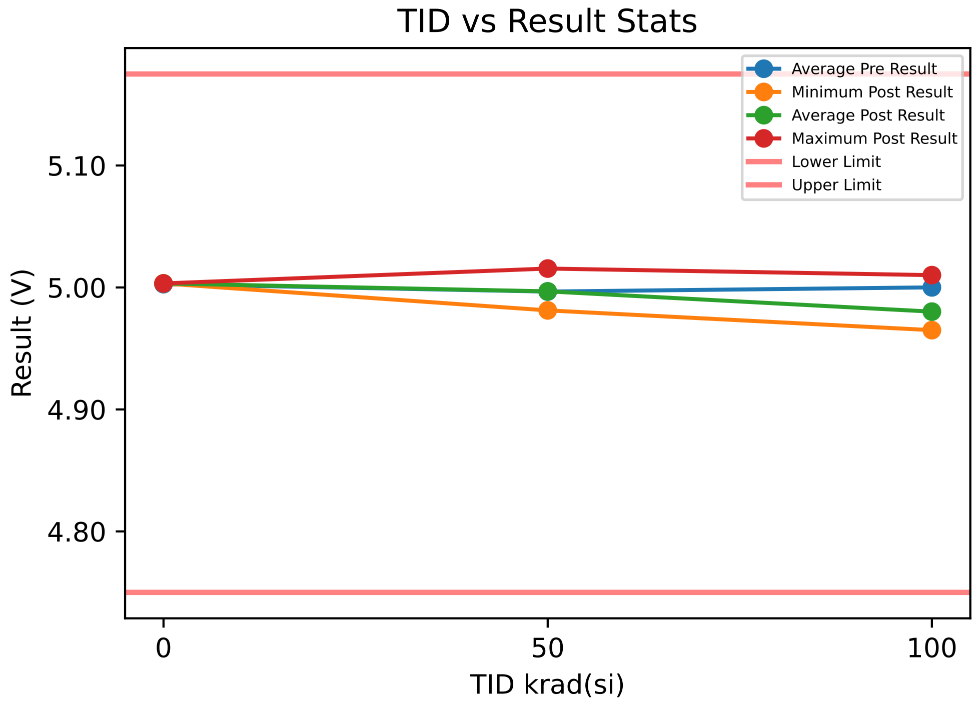
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

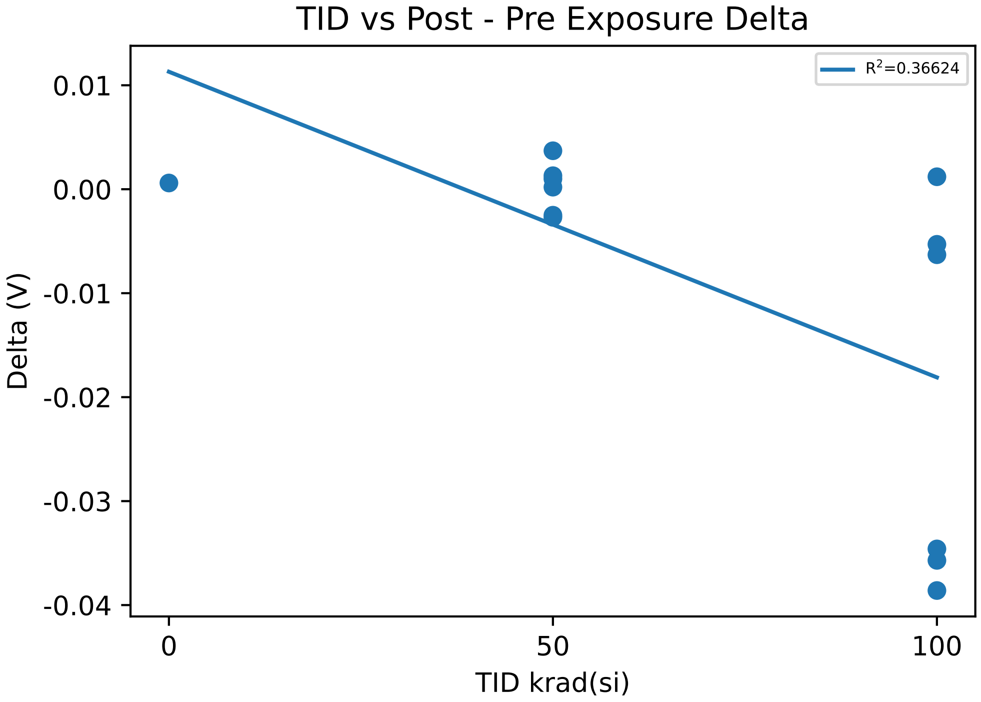
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0599	7.0548	-0.0051
60	50	Biased	7.0232	7.0149	-0.0083
61	50	Biased	7.0409	7.0429	0.002
63	100	Biased	7.0437	7.052	0.0083
64	100	Biased	7.039	7.0163	-0.0227
65	100	Biased	7.068	7.0681	0.0001
66	50	Unbiased	7.0259	7.0234	-0.0025
67	50	Unbiased	7.0213	7.0348	0.0135
68	50	Unbiased	7.0816	7.087	0.0054
69	100	Unbiased	7.032	7.0511	0.0191
70	100	Unbiased	6.9726	6.9976	0.025
71	100	Unbiased	7.0548	7.0271	-0.0277
72	0	Control	7.0646	7.064	-0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0646	7.0646	7.0646		7.064	7.064	7.064		-0.0006	-0.0006	-0.0006	
50	7.0213	7.0421	7.0816	0.024211	7.0149	7.043	7.087	0.025754	-0.0083	0.00083333	0.0135	0.0079043
100	6.9726	7.035	7.068	0.033092	6.9976	7.0354	7.0681	0.026283	-0.0277	0.00035	0.025	0.021636

Device Test: 60.1 V_BP5L PWM 500kHz VIN_10V





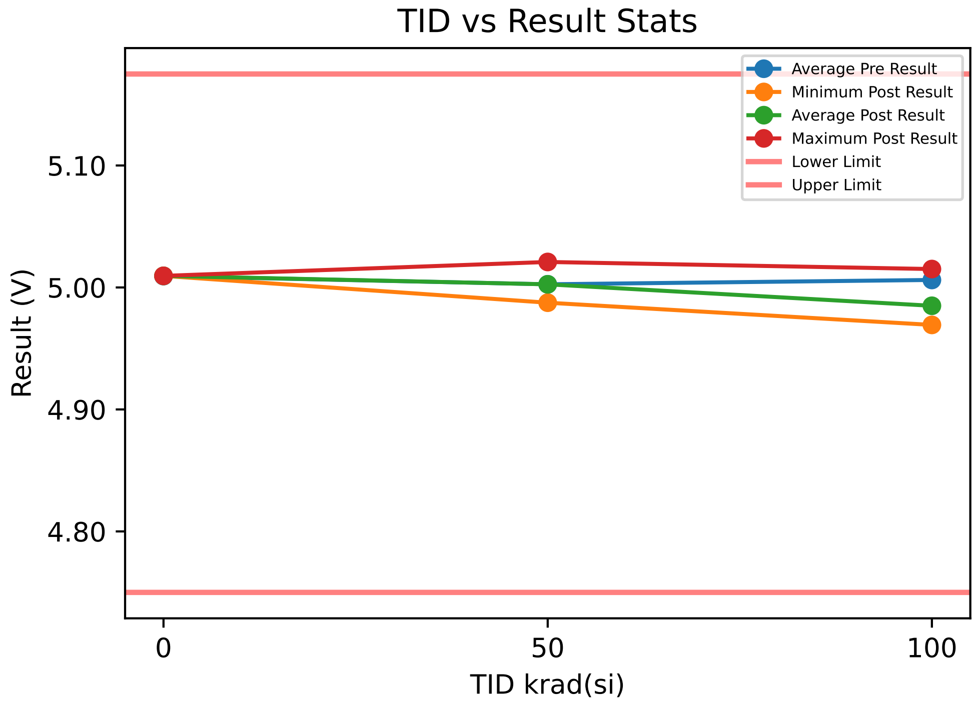
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

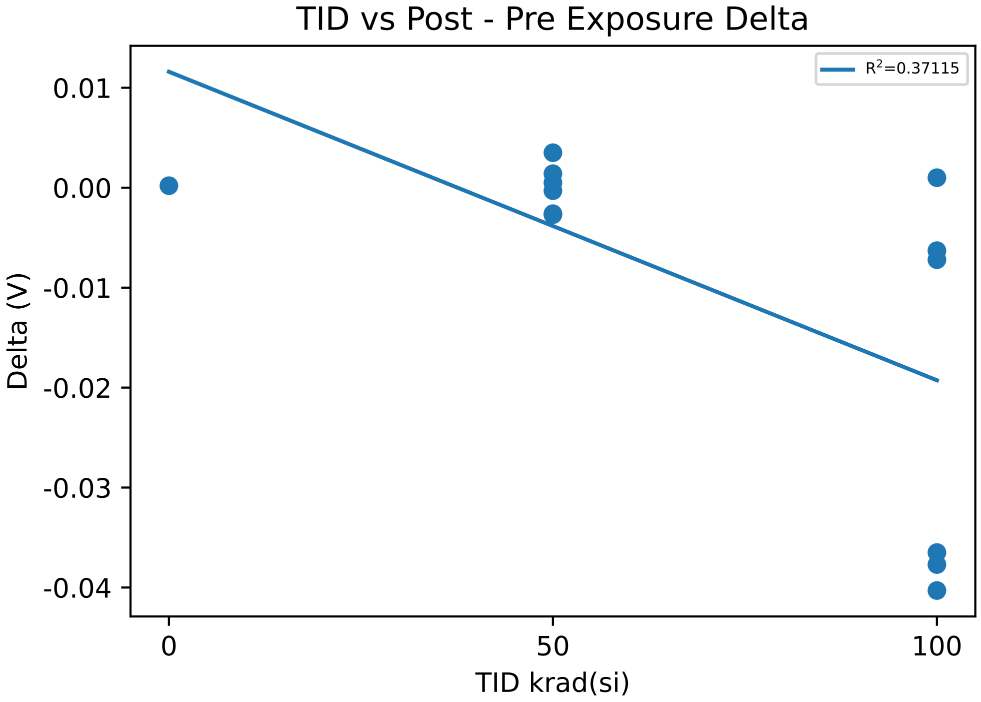
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0015	5.0017	0.0002
60	50	Biased	4.982	4.9857	0.0037
61	50	Biased	5.0067	5.008	0.0013
63	100	Biased	5.0014	4.9657	-0.0357
64	100	Biased	4.9889	4.9826	-0.0063
65	100	Biased	4.9997	4.9651	-0.0346
66	50	Unbiased	4.9839	4.9812	-0.0027
67	50	Unbiased	4.9877	4.9887	0.001
68	50	Unbiased	5.018	5.0155	-0.0025
69	100	Unbiased	5.0154	5.0101	-0.0053
70	100	Unbiased	4.9914	4.9926	0.0012
71	100	Unbiased	5.0036	4.965	-0.0386
72	0	Control	5.0027	5.0033	0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0027	5.0027	5.0027		5.0033	5.0033	5.0033		0.0006	0.0006	0.0006	
50	4.982	4.9966	5.018	0.014406	4.9812	4.9968	5.0155	0.013648	-0.0027	0.00016667	0.0037	0.002441
100	4.9889	5.0001	5.0154	0.0094796	4.965	4.9802	5.0101	0.018562	-0.0386	-0.019883	0.0012	0.018214

Device Test: 60.10 V_BP5L PWM 5MHz VIN_10V





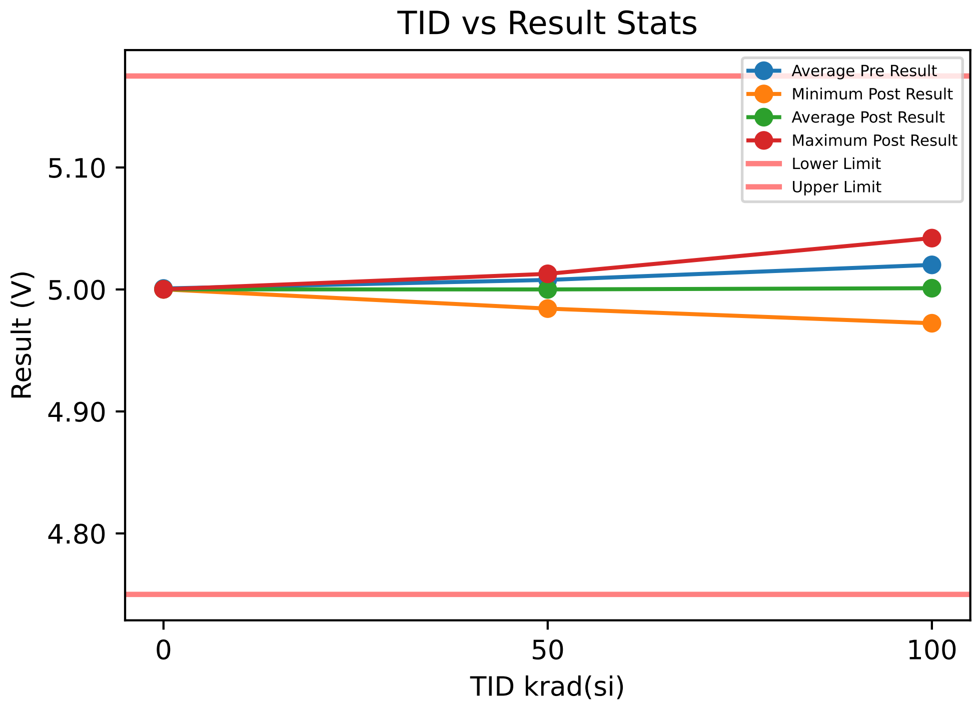
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

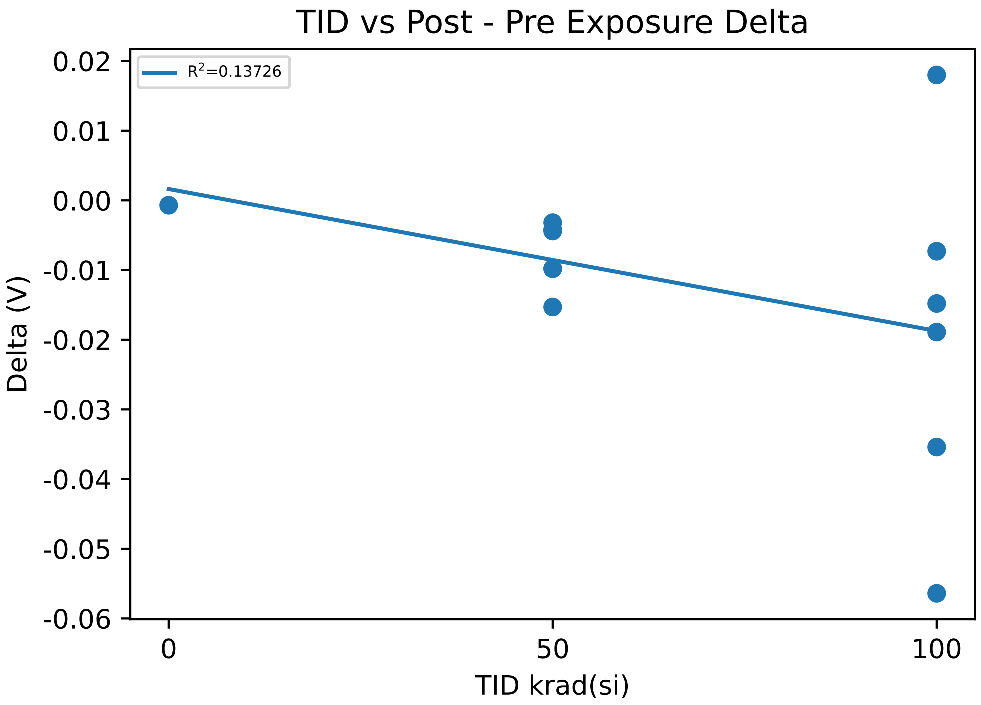
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0075	5.0072	-0.0003
60	50	Biased	4.9877	4.9912	0.0035
61	50	Biased	5.0128	5.0142	0.0014
63	100	Biased	5.0072	4.9695	-0.0377
64	100	Biased	4.995	4.9878	-0.0072
65	100	Biased	5.006	4.9695	-0.0365
66	50	Unbiased	4.9902	4.9875	-0.0027
67	50	Unbiased	4.9939	4.9944	0.0005
68	50	Unbiased	5.0235	5.0209	-0.0026
69	100	Unbiased	5.0214	5.0151	-0.0063
70	100	Unbiased	4.9977	4.9987	0.001
71	100	Unbiased	5.0096	4.9693	-0.0403
72	0	Control	5.0093	5.0095	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0093	5.0093	5.0093		5.0095	5.0095	5.0095		0.0002	0.0002	0.0002	
50	4.9877	5.0026	5.0235	0.014257	4.9875	5.0026	5.0209	0.013534	-0.0027	-3.3333e-05	0.0035	0.0023914
100	4.995	5.0061	5.0214	0.0093948	4.9693	4.985	5.0151	0.019123	-0.0403	-0.021167	0.001	0.018879

Device Test: 60.11 V_BP5H PWM 5MHz VIN_10V





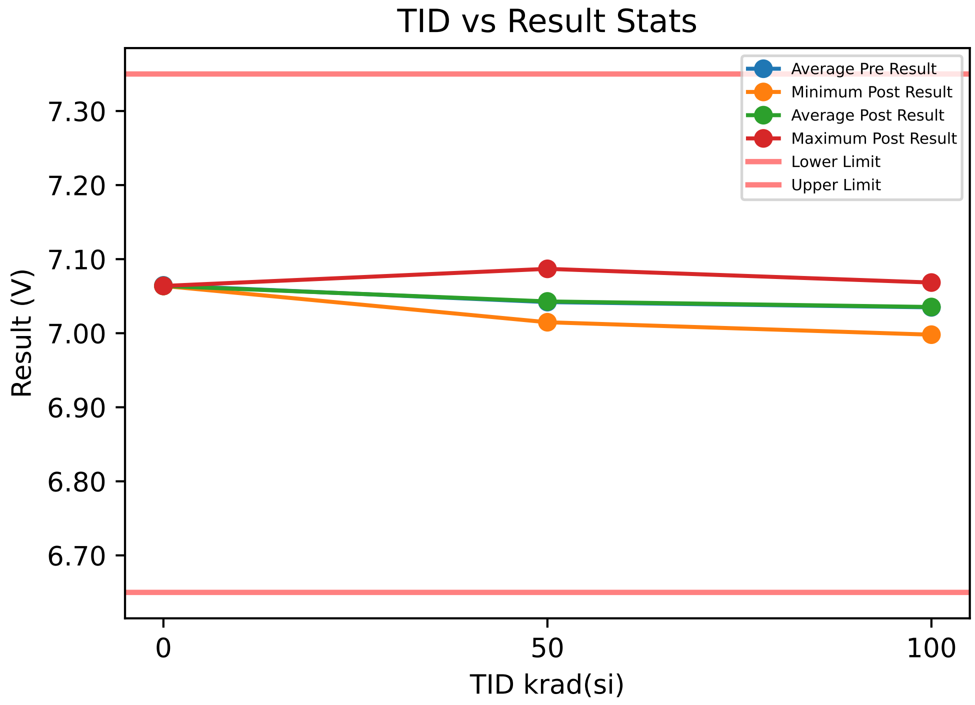
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

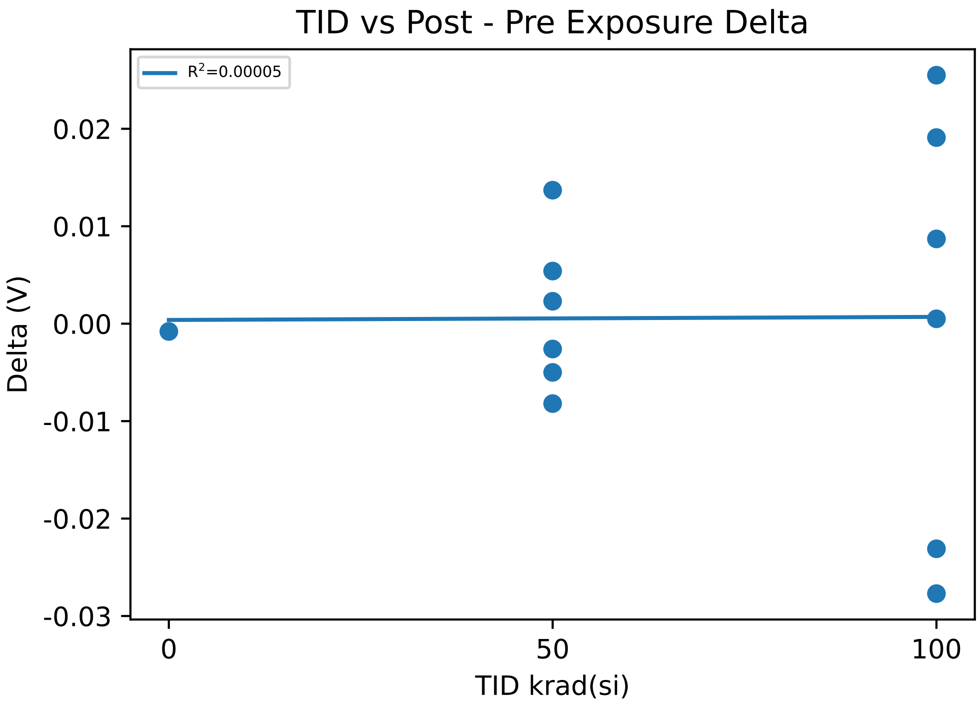
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0118	5.0074	-0.0044
60	50	Biased	5.0009	4.9911	-0.0098
61	50	Biased	5.0129	5.0097	-0.0032
63	100	Biased	5.007	4.9881	-0.0189
64	100	Biased	5.0312	4.9958	-0.0354
65	100	Biased	5.0285	5.0212	-0.0073
66	50	Unbiased	4.9941	4.9843	-0.0098
67	50	Unbiased	4.9991	4.9949	-0.0042
68	50	Unbiased	5.0281	5.0128	-0.0153
69	100	Unbiased	5.0287	4.9723	-0.0564
70	100	Unbiased	5.0014	4.9866	-0.0148
71	100	Unbiased	5.0241	5.0421	0.018
72	0	Control	5.0008	5.0001	-0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0008	5.0008	5.0008		5.0001	5.0001	5.0001		-0.0007	-0.0007	-0.0007	
50	4.9941	5.0078	5.0281	0.01237	4.9843	5	5.0128	0.011527	-0.0153	-0.0077833	-0.0032	0.0046889
100	5.0014	5.0202	5.0312	0.012689	4.9723	5.001	5.0421	0.025775	-0.0564	-0.019133	0.018	0.025263

Device Test: 60.12 V_BP7L IIM 500kHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

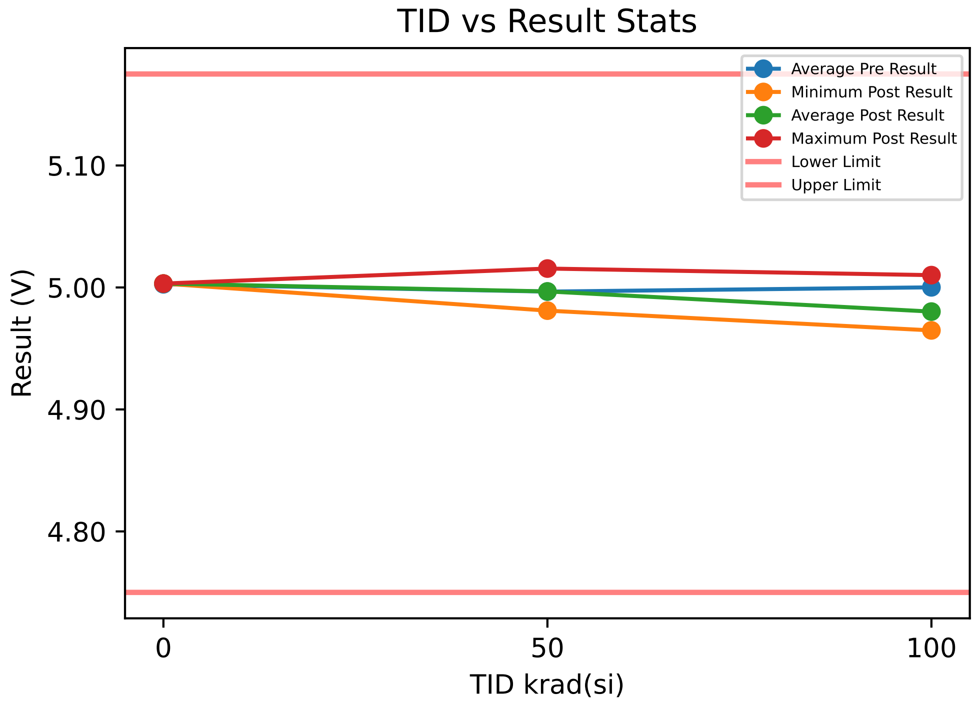
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

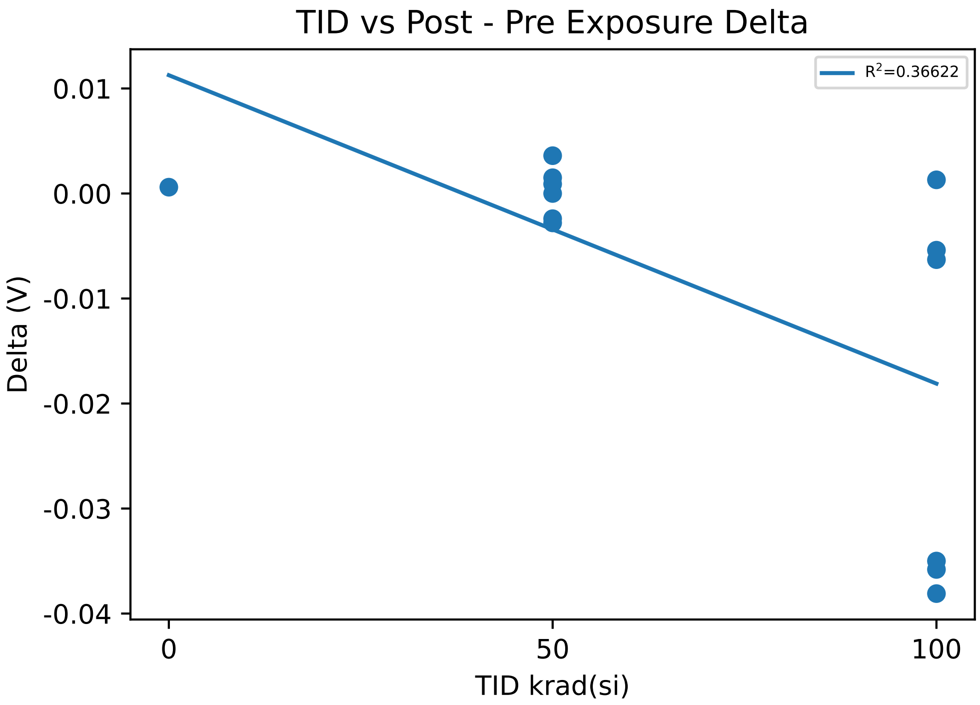
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0596	7.0546	-0.005
60	50	Biased	7.023	7.0148	-0.0082
61	50	Biased	7.0408	7.0431	0.0023
63	100	Biased	7.0435	7.0522	0.0087
64	100	Biased	7.0389	7.0158	-0.0231
65	100	Biased	7.0679	7.0684	0.0005
66	50	Unbiased	7.0258	7.0232	-0.0026
67	50	Unbiased	7.0212	7.0349	0.0137
68	50	Unbiased	7.0815	7.0869	0.0054
69	100	Unbiased	7.0319	7.051	0.0191
70	100	Unbiased	6.9725	6.998	0.0255
71	100	Unbiased	7.0546	7.0269	-0.0277
72	0	Control	7.0646	7.0638	-0.0008

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0646	7.0646	7.0646		7.0638	7.0638	7.0638		-0.0008	-0.0008	-0.0008	
50	7.0212	7.042	7.0815	0.024197	7.0148	7.0429	7.0869	0.025747	-0.0082	0.00093333	0.0137	0.0079488
100	6.9725	7.0349	7.0679	0.033075	6.998	7.0354	7.0684	0.026343	-0.0277	0.0005	0.0255	0.021865

Device Test: 60.13 V_BP5L IIM 500kHz VIN_10V





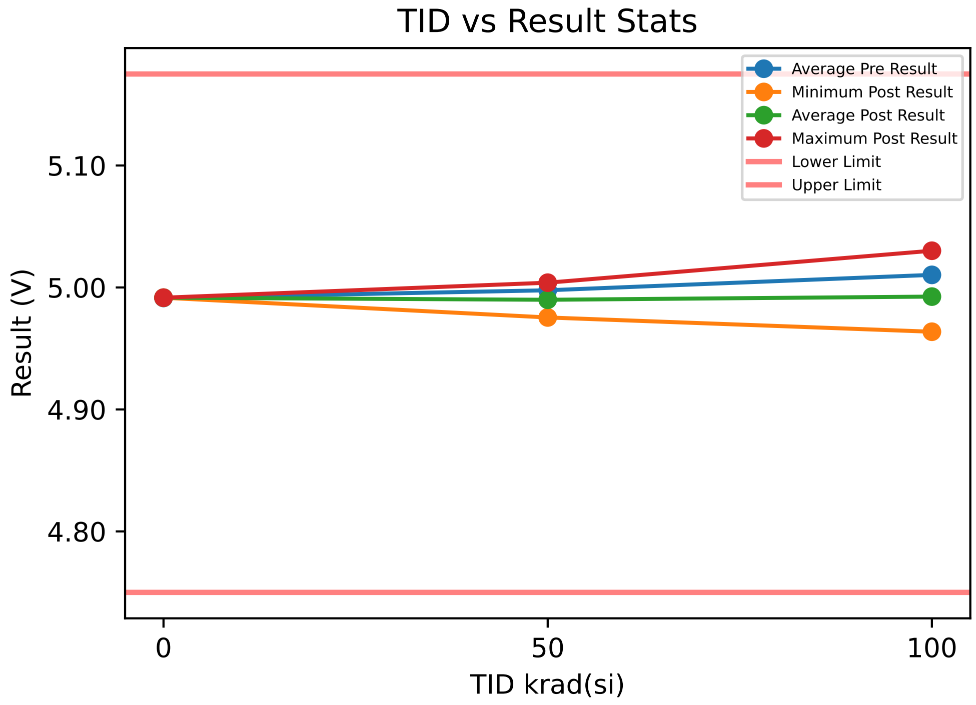
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

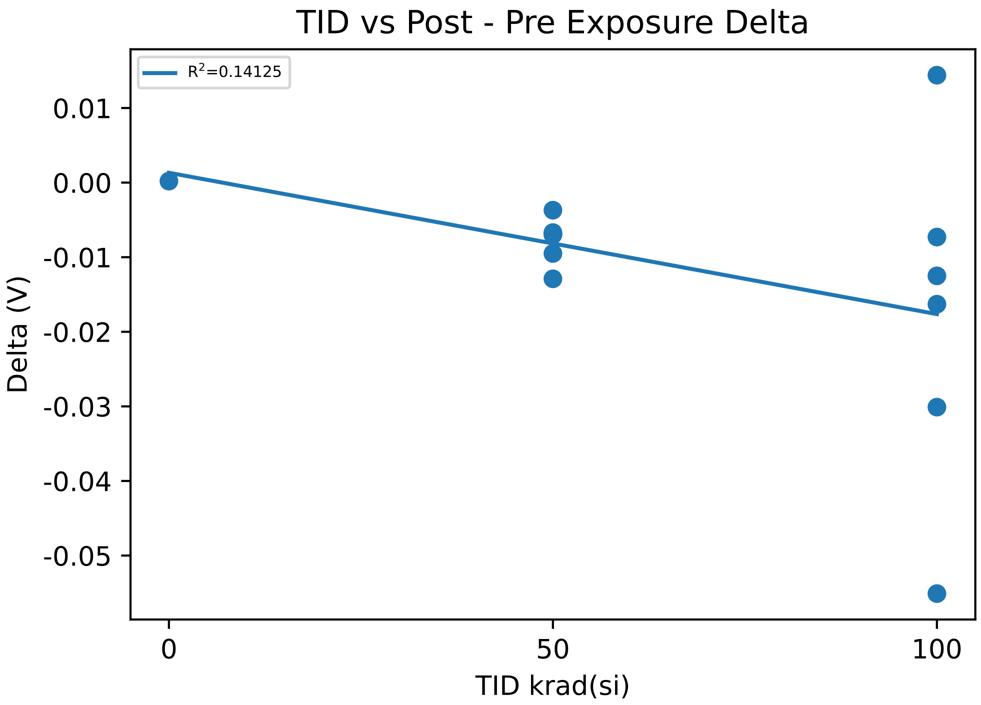
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0016	5.0016	0
60	50	Biased	4.982	4.9856	0.0036
61	50	Biased	5.0066	5.0081	0.0015
63	100	Biased	5.0015	4.9657	-0.0358
64	100	Biased	4.9889	4.9826	-0.0063
65	100	Biased	4.9998	4.9648	-0.035
66	50	Unbiased	4.9838	4.981	-0.0028
67	50	Unbiased	4.9878	4.9887	0.0009
68	50	Unbiased	5.0179	5.0155	-0.0024
69	100	Unbiased	5.0155	5.0101	-0.0054
70	100	Unbiased	4.9914	4.9927	0.0013
71	100	Unbiased	5.0035	4.9654	-0.0381
72	0	Control	5.0026	5.0032	0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0026	5.0026	5.0026		5.0032	5.0032	5.0032		0.0006	0.0006	0.0006	
50	4.982	4.9966	5.0179	0.014374	4.981	4.9967	5.0155	0.013719	-0.0028	0.00013333	0.0036	0.0024295
100	4.9889	5.0001	5.0155	0.0095068	4.9648	4.9802	5.0101	0.018561	-0.0381	-0.019883	0.0013	0.018203

Device Test: 60.14 V_BP5H IIM 500kHz VIN_10V





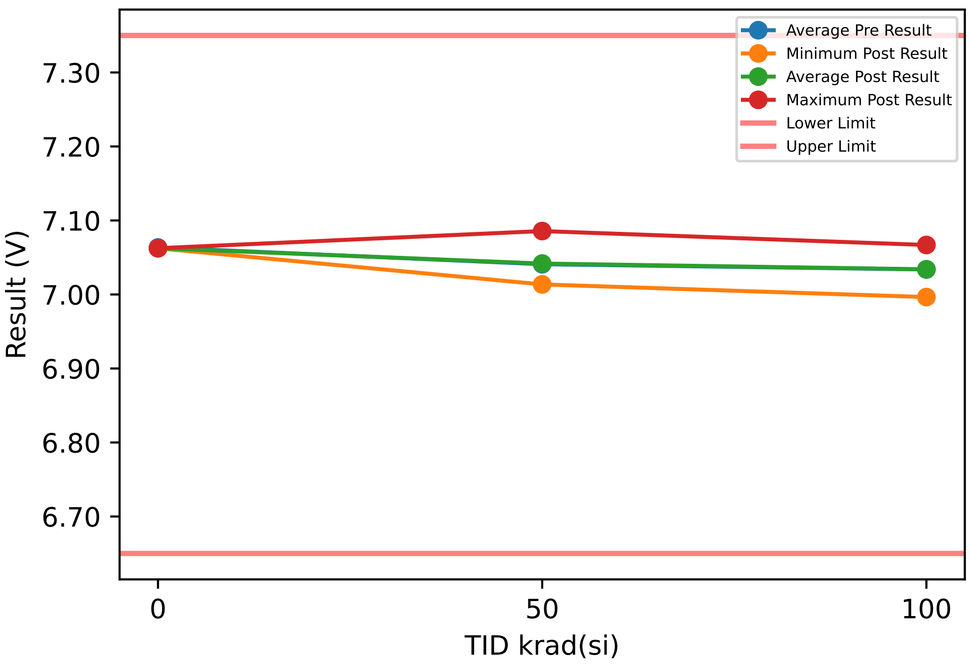
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

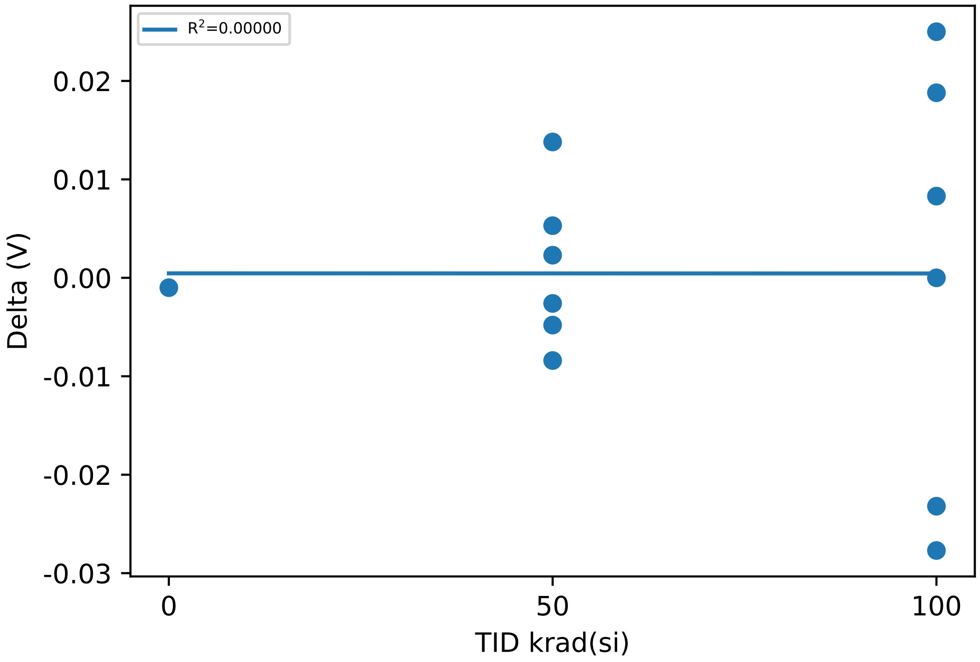
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0023	4.9956	-0.0067
60	50	Biased	4.9893	4.9823	-0.007
61	50	Biased	5.0021	4.9984	-0.0037
63	100	Biased	4.9976	4.9813	-0.0163
64	100	Biased	5.0197	4.9896	-0.0301
65	100	Biased	5.0201	5.0128	-0.0073
66	50	Unbiased	4.9849	4.9754	-0.0095
67	50	Unbiased	4.9907	4.9838	-0.0069
68	50	Unbiased	5.0168	5.0039	-0.0129
69	100	Unbiased	5.0188	4.9637	-0.0551
70	100	Unbiased	4.99	4.9775	-0.0125
71	100	Unbiased	5.0157	5.0301	0.0144
72	0	Control	4.9914	4.9916	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9914	4.9914	4.9914		4.9916	4.9916	4.9916		0.0002	0.0002	0.0002	
50	4.9849	4.9977	5.0168	0.011737	4.9754	4.9899	5.0039	0.011009	-0.0129	-0.0077833	-0.0037	0.0031103
100	4.99	5.0103	5.0201	0.013109	4.9637	4.9925	5.0301	0.024553	-0.0551	-0.017817	0.0144	0.023324

Device Test: 60.15 V_BP7L IIM 1MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

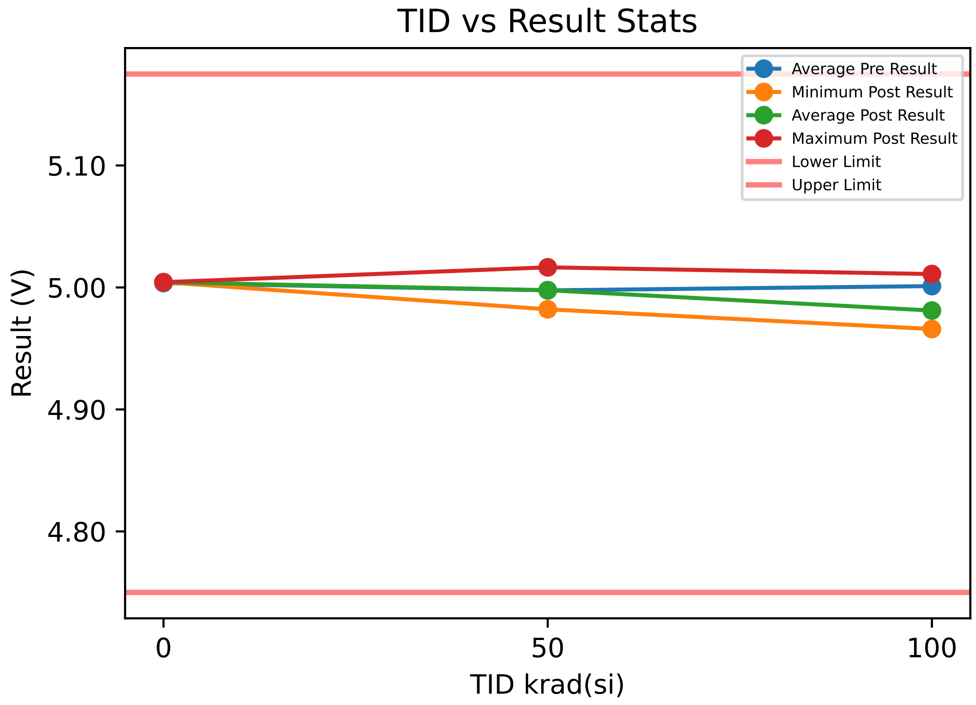
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

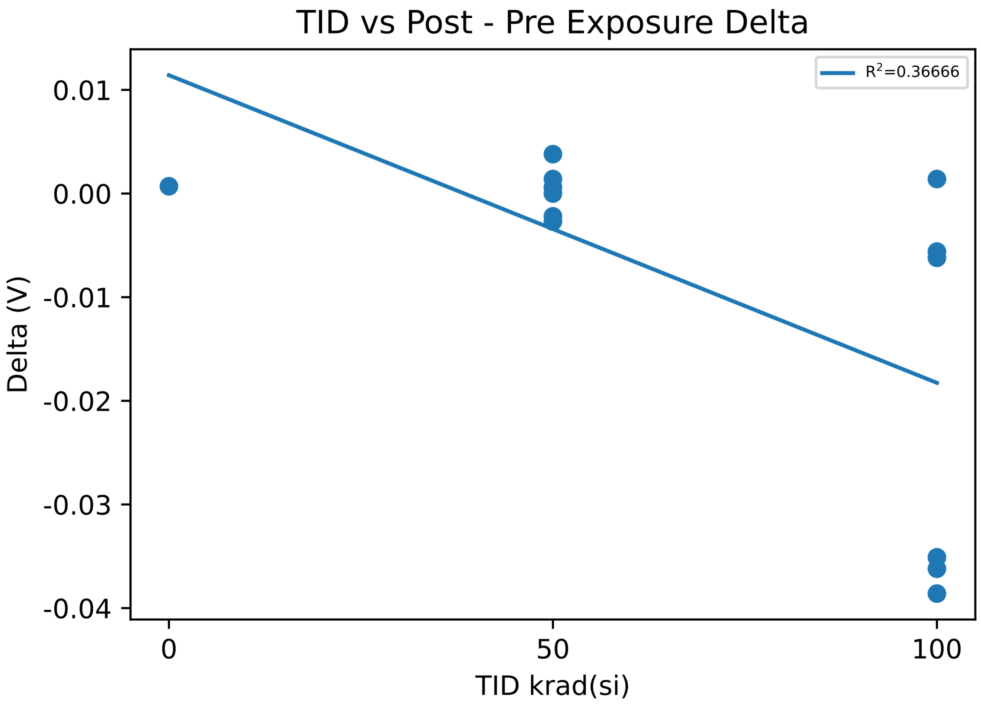
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0585	7.0537	-0.0048
60	50	Biased	7.022	7.0136	-0.0084
61	50	Biased	7.0396	7.0419	0.0023
63	100	Biased	7.0425	7.0508	0.0083
64	100	Biased	7.0378	7.0146	-0.0232
65	100	Biased	7.0669	7.0669	0
66	50	Unbiased	7.0247	7.0221	-0.0026
67	50	Unbiased	7.02	7.0338	0.0138
68	50	Unbiased	7.0804	7.0857	0.0053
69	100	Unbiased	7.0307	7.0495	0.0188
70	100	Unbiased	6.9715	6.9965	0.025
71	100	Unbiased	7.0535	7.0258	-0.0277
72	0	Control	7.0635	7.0625	-0.001

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0635	7.0635	7.0635		7.0625	7.0625	7.0625		-0.001	-0.001	-0.001	
50	7.02	7.0409	7.0804	0.0242	7.0136	7.0418	7.0857	0.025753	-0.0084	0.00093333	0.0138	0.0079869
100	6.9715	7.0338	7.0669	0.033064	6.9965	7.034	7.0669	0.026286	-0.0277	0.0002	0.025	0.021692

Device Test: 60.16 V_BP5L IIM 1MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

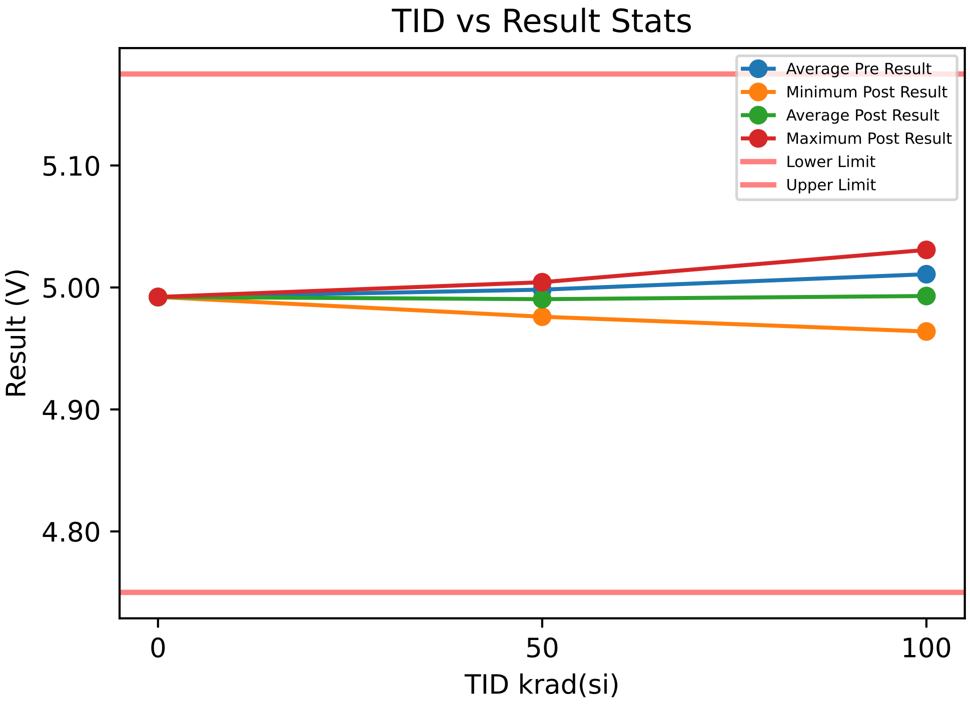
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

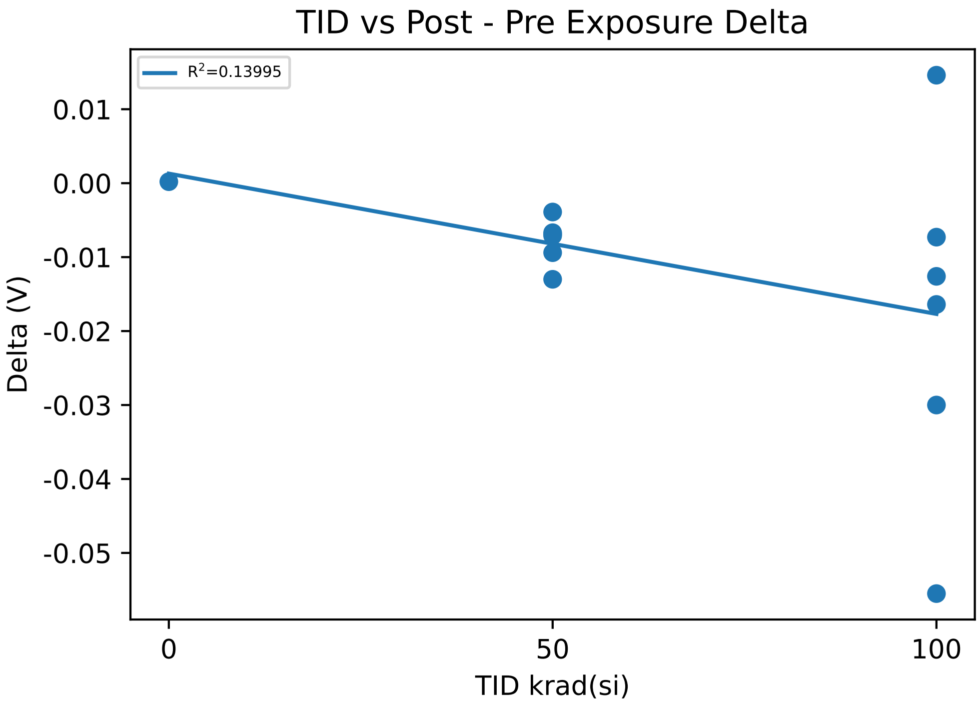
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0027	5.0027	0
60	50	Biased	4.9828	4.9866	0.0038
61	50	Biased	5.0077	5.0091	0.0014
63	100	Biased	5.0026	4.9664	-0.0362
64	100	Biased	4.9896	4.9834	-0.0062
65	100	Biased	5.001	4.9659	-0.0351
66	50	Unbiased	4.9848	4.9821	-0.0027
67	50	Unbiased	4.989	4.9896	0.0006
68	50	Unbiased	5.0187	5.0165	-0.0022
69	100	Unbiased	5.0166	5.011	-0.0056
70	100	Unbiased	4.9923	4.9937	0.0014
71	100	Unbiased	5.0046	4.966	-0.0386
72	0	Control	5.0036	5.0043	0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0036	5.0036	5.0036		5.0043	5.0043	5.0043		0.0007	0.0007	0.0007	
50	4.9828	4.9976	5.0187	0.014353	4.9821	4.9978	5.0165	0.013715	-0.0027	0.00015	0.0038	0.0023981
100	4.9896	5.0011	5.0166	0.0096379	4.9659	4.9811	5.011	0.018618	-0.0386	-0.02005	0.0014	0.018396

Device Test: 60.17 V_BP5H IIM 1MHz VIN_10V





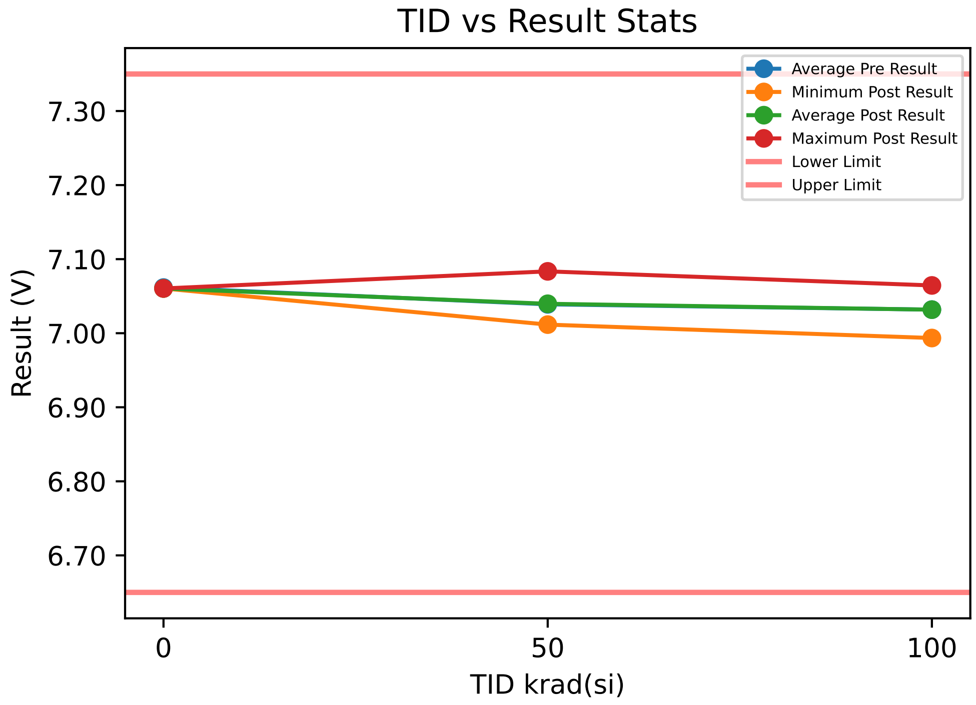
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

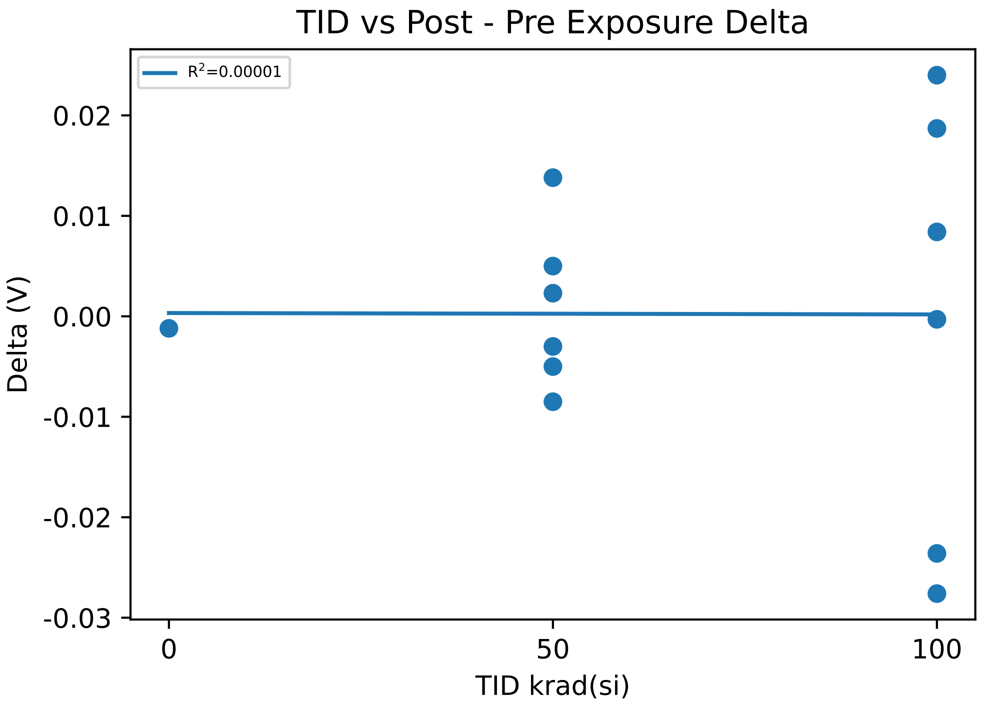
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0029	4.9962	-0.0067
60	50	Biased	4.9898	4.9829	-0.0069
61	50	Biased	5.0026	4.9987	-0.0039
63	100	Biased	4.9982	4.9818	-0.0164
64	100	Biased	5.0201	4.9901	-0.03
65	100	Biased	5.0206	5.0133	-0.0073
66	50	Unbiased	4.9854	4.976	-0.0094
67	50	Unbiased	4.9913	4.9842	-0.0071
68	50	Unbiased	5.0173	5.0043	-0.013
69	100	Unbiased	5.0194	4.9639	-0.0555
70	100	Unbiased	4.9906	4.978	-0.0126
71	100	Unbiased	5.0162	5.0308	0.0146
72	0	Control	4.992	4.9922	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.992	4.992	4.992		4.9922	4.9922	4.9922		0.0002	0.0002	0.0002	
50	4.9854	4.9982	5.0173	0.011733	4.976	4.9904	5.0043	0.010934	-0.013	-0.0078333	-0.0039	0.0030761
100	4.9906	5.0109	5.0206	0.013057	4.9639	4.993	5.0308	0.024684	-0.0555	-0.017867	0.0146	0.023491

Device Test: 60.18 V_BP7L IIM 2MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

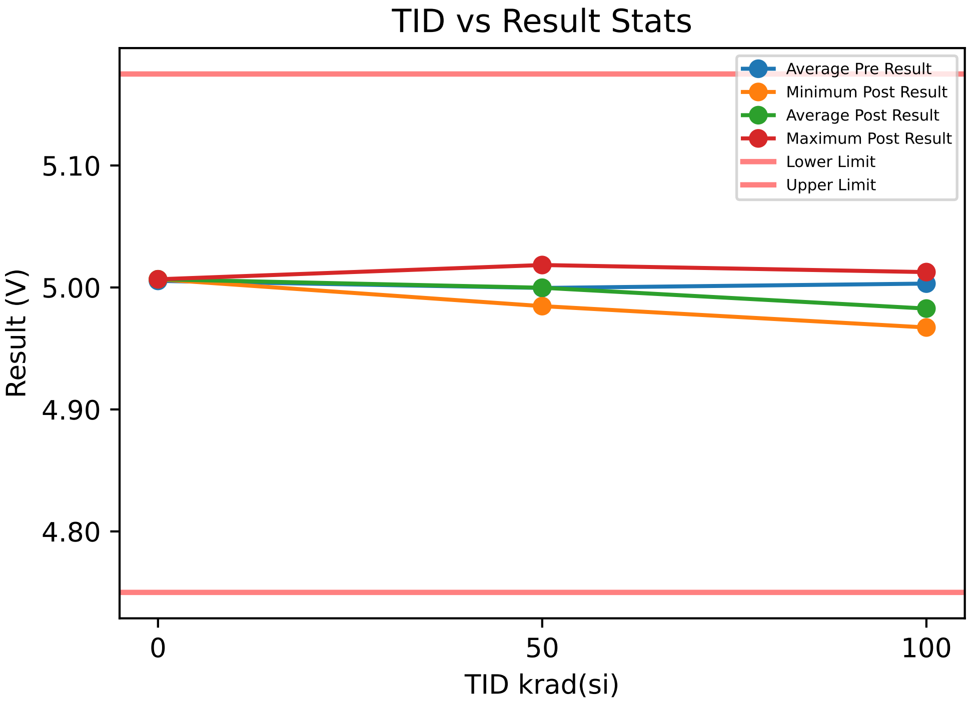
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

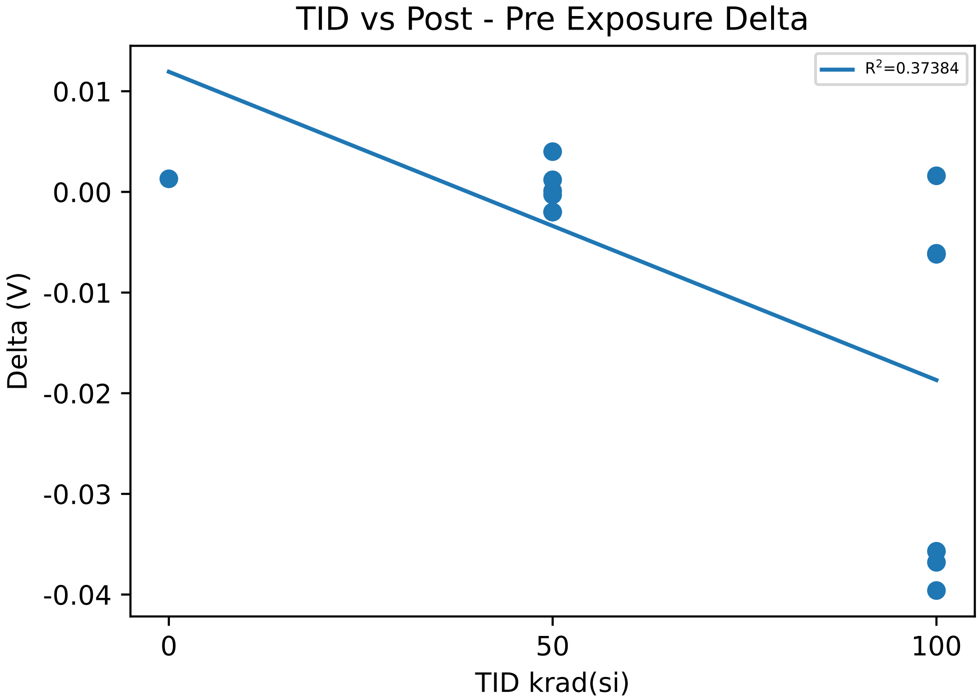
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0566	7.0516	-0.005
60	50	Biased	7.0201	7.0116	-0.0085
61	50	Biased	7.0377	7.04	0.0023
63	100	Biased	7.0406	7.049	0.0084
64	100	Biased	7.036	7.0124	-0.0236
65	100	Biased	7.0648	7.0645	-0.0003
66	50	Unbiased	7.0228	7.0198	-0.003
67	50	Unbiased	7.0181	7.0319	0.0138
68	50	Unbiased	7.0785	7.0835	0.005
69	100	Unbiased	7.0288	7.0475	0.0187
70	100	Unbiased	6.9695	6.9935	0.024
71	100	Unbiased	7.0514	7.0238	-0.0276
72	0	Control	7.0616	7.0604	-0.0012

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0616	7.0616	7.0616		7.0604	7.0604	7.0604		-0.0012	-0.0012	-0.0012	
50	7.0181	7.039	7.0785	0.0242	7.0116	7.0397	7.0835	0.025716	-0.0085	0.00076667	0.0138	0.0080431
100	6.9695	7.0318	7.0648	0.033041	6.9935	7.0318	7.0645	0.026529	-0.0276	-6.6667e-05	0.024	0.021518

Device Test: 60.19 V_BP5L IIM 2MHz VIN_10V





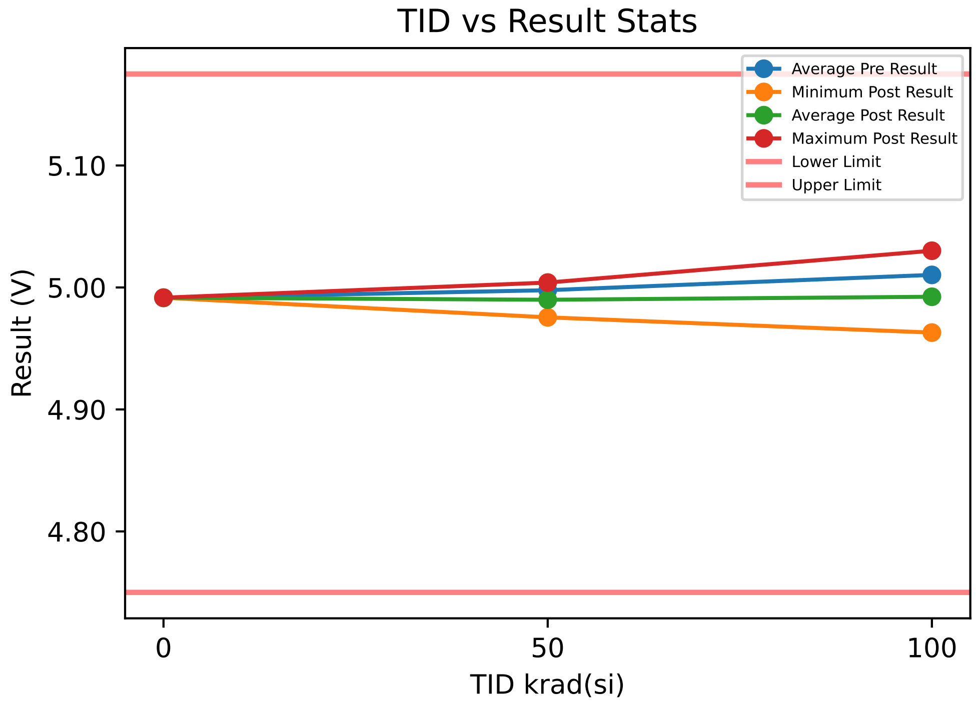
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

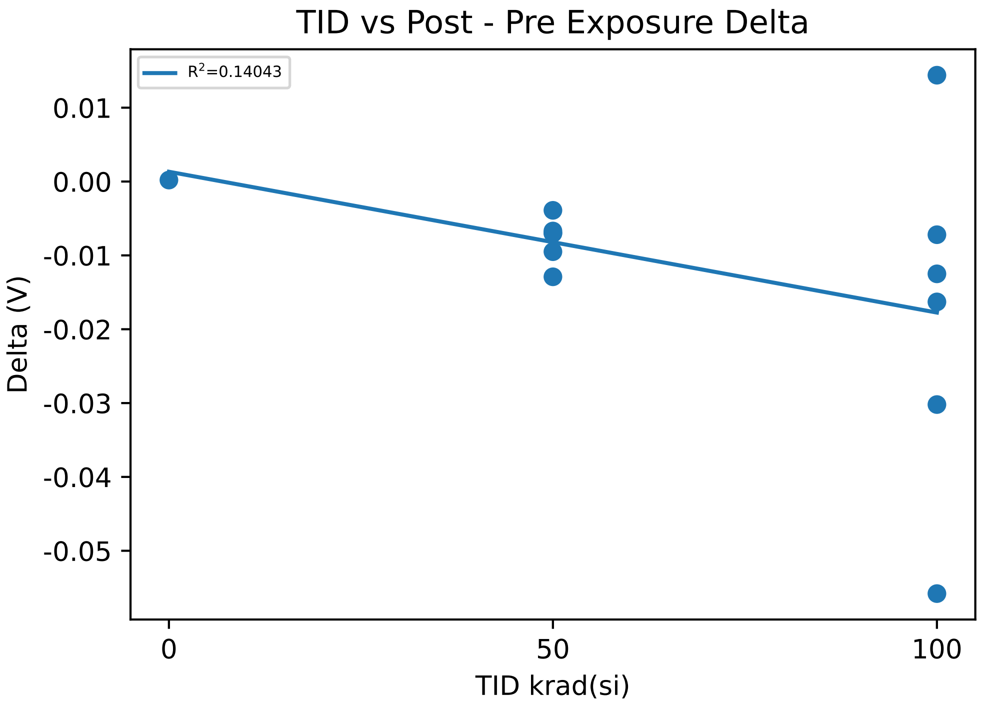
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.005	5.0047	-0.0003
60	50	Biased	4.9844	4.9884	0.004
61	50	Biased	5.0098	5.011	0.0012
63	100	Biased	5.0045	4.9677	-0.0368
64	100	Biased	4.9912	4.9851	-0.0061
65	100	Biased	5.0035	4.9678	-0.0357
66	50	Unbiased	4.9867	4.9847	-0.002
67	50	Unbiased	4.9913	4.9914	0.0001
68	50	Unbiased	5.0204	5.0184	-0.002
69	100	Unbiased	5.0188	5.0126	-0.0062
70	100	Unbiased	4.9942	4.9958	0.0016
71	100	Unbiased	5.0068	4.9672	-0.0396
72	0	Control	5.0054	5.0067	0.0013

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0054	5.0054	5.0054		5.0067	5.0067	5.0067		0.0013	0.0013	0.0013	
50	4.9844	4.9996	5.0204	0.014368	4.9847	4.9998	5.0184	0.013594	-0.002	0.00016667	0.004	0.0022527
100	4.9912	5.0032	5.0188	0.0098295	4.9672	4.9827	5.0126	0.018754	-0.0396	-0.020467	0.0016	0.018771

Device Test: 60.2 V_BP5H PWM 500kHz VIN_10V





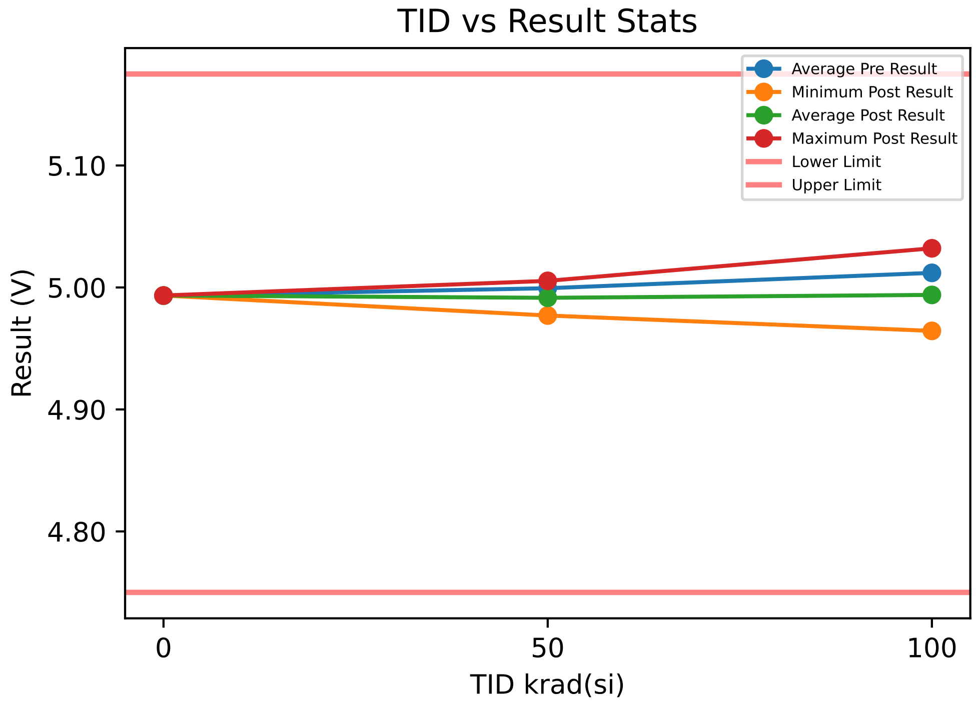
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

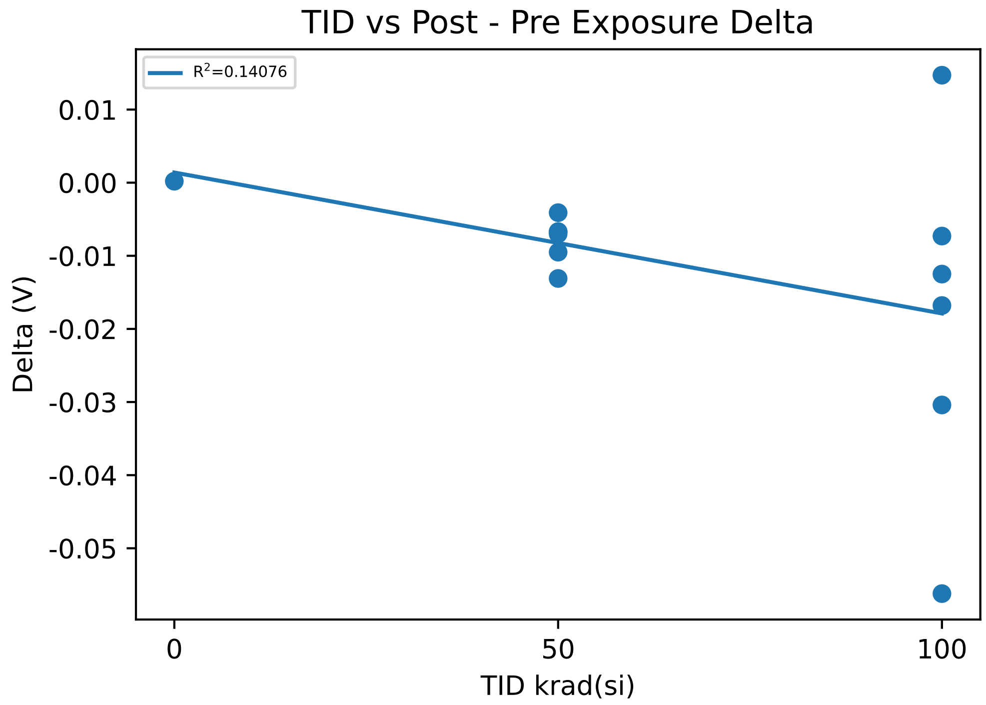
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0024	4.9957	-0.0067
60	50	Biased	4.9893	4.9823	-0.007
61	50	Biased	5.0022	4.9983	-0.0039
63	100	Biased	4.9977	4.9814	-0.0163
64	100	Biased	5.0197	4.9895	-0.0302
65	100	Biased	5.0199	5.0127	-0.0072
66	50	Unbiased	4.985	4.9755	-0.0095
67	50	Unbiased	4.9907	4.9837	-0.007
68	50	Unbiased	5.0169	5.004	-0.0129
69	100	Unbiased	5.0188	4.963	-0.0558
70	100	Unbiased	4.99	4.9775	-0.0125
71	100	Unbiased	5.0157	5.0301	0.0144
72	0	Control	4.9914	4.9916	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9914	4.9914	4.9914		4.9916	4.9916	4.9916		0.0002	0.0002	0.0002	
50	4.985	4.9977	5.0169	0.011763	4.9755	4.9899	5.004	0.011014	-0.0129	-0.0078333	-0.0039	0.0030526
100	4.99	5.0103	5.0199	0.01306	4.963	4.9924	5.0301	0.024695	-0.0558	-0.017933	0.0144	0.023568

Device Test: 60.20 V_BP5H IIM 2MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

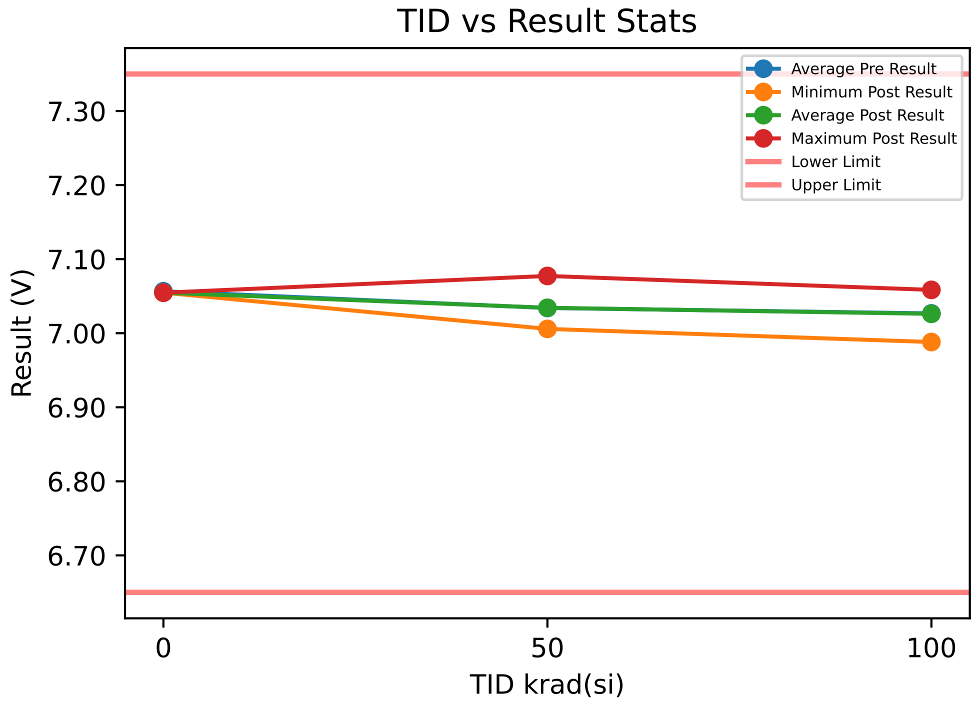
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

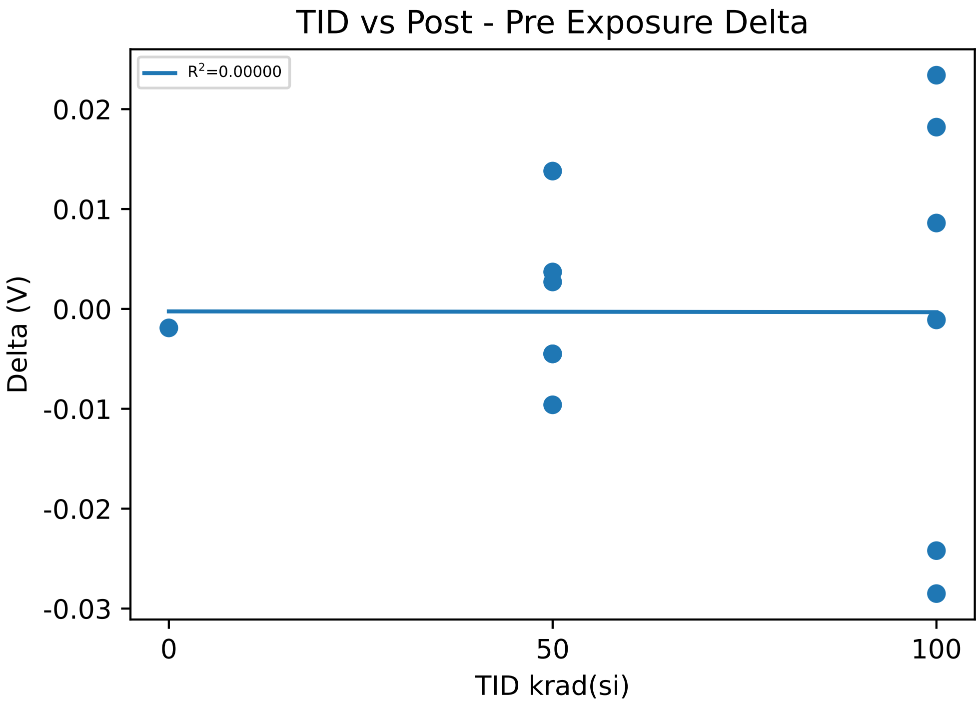
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.004	4.9973	-0.0067
60	50	Biased	4.9908	4.9841	-0.0067
61	50	Biased	5.0039	4.9998	-0.0041
63	100	Biased	4.9994	4.9826	-0.0168
64	100	Biased	5.0211	4.9907	-0.0304
65	100	Biased	5.0217	5.0144	-0.0073
66	50	Unbiased	4.9865	4.977	-0.0095
67	50	Unbiased	4.9925	4.9855	-0.007
68	50	Unbiased	5.0185	5.0054	-0.0131
69	100	Unbiased	5.0206	4.9644	-0.0562
70	100	Unbiased	4.9916	4.9791	-0.0125
71	100	Unbiased	5.0174	5.0321	0.0147
72	0	Control	4.9932	4.9934	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9932	4.9932	4.9932		4.9934	4.9934	4.9934		0.0002	0.0002	0.0002	
50	4.9865	4.9994	5.0185	0.011783	4.977	4.9915	5.0054	0.010925	-0.0131	-0.00785	-0.0041	0.0030892
100	4.9916	5.012	5.0217	0.013076	4.9644	4.9939	5.0321	0.024927	-0.0562	-0.018083	0.0147	0.023784

Device Test: 60.21 V_BP7L IIM 5MHz VIN_10V





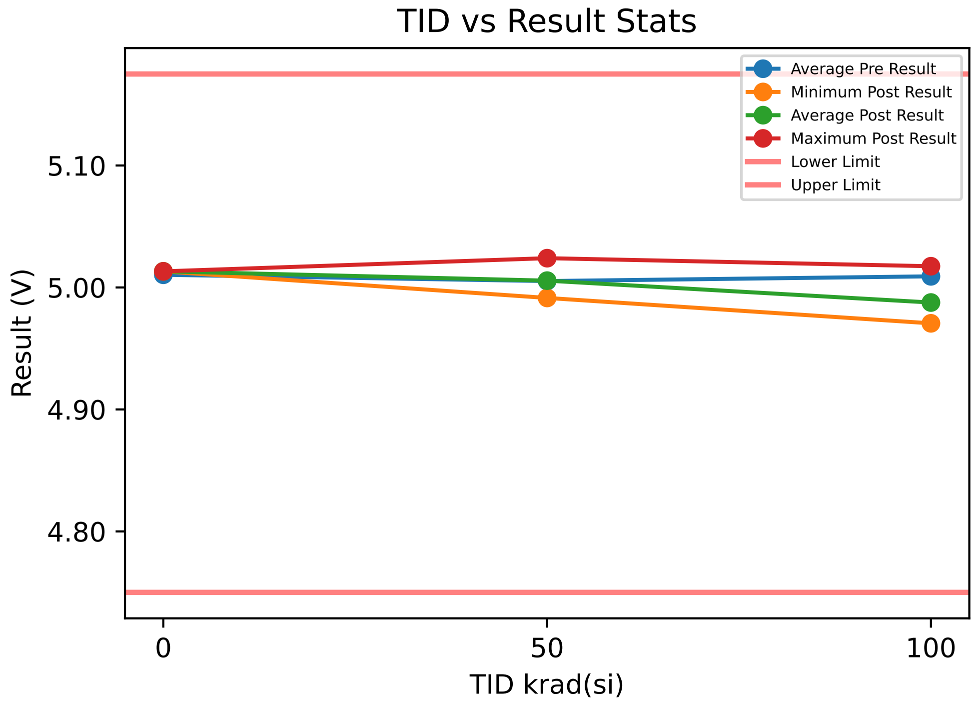
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

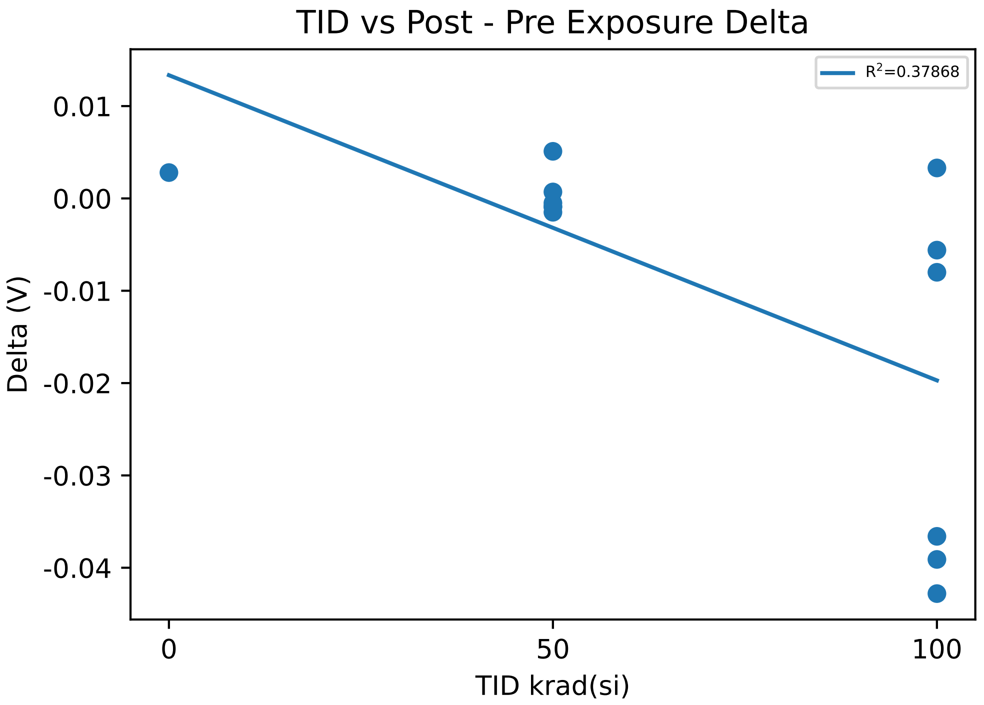
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0514	7.0469	-0.0045
60	50	Biased	7.0154	7.0058	-0.0096
61	50	Biased	7.0326	7.0353	0.0027
63	100	Biased	7.0355	7.0441	0.0086
64	100	Biased	7.031	7.0068	-0.0242
65	100	Biased	7.0596	7.0585	-0.0011
66	50	Unbiased	7.0183	7.0138	-0.0045
67	50	Unbiased	7.013	7.0268	0.0138
68	50	Unbiased	7.0736	7.0773	0.0037
69	100	Unbiased	7.0236	7.0418	0.0182
70	100	Unbiased	6.9647	6.9881	0.0234
71	100	Unbiased	7.046	7.0175	-0.0285
72	0	Control	7.0566	7.0547	-0.0019

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0566	7.0566	7.0566		7.0547	7.0547	7.0547		-0.0019	-0.0019	-0.0019	
50	7.013	7.0341	7.0736	0.024109	7.0058	7.0343	7.0773	0.025681	-0.0096	0.00026667	0.0138	0.0082904
100	6.9647	7.0267	7.0596	0.032877	6.9881	7.0261	7.0585	0.026498	-0.0285	-0.0006	0.0234	0.021678

Device Test: 60.22 V_BP5L IIM 5MHz VIN_10V





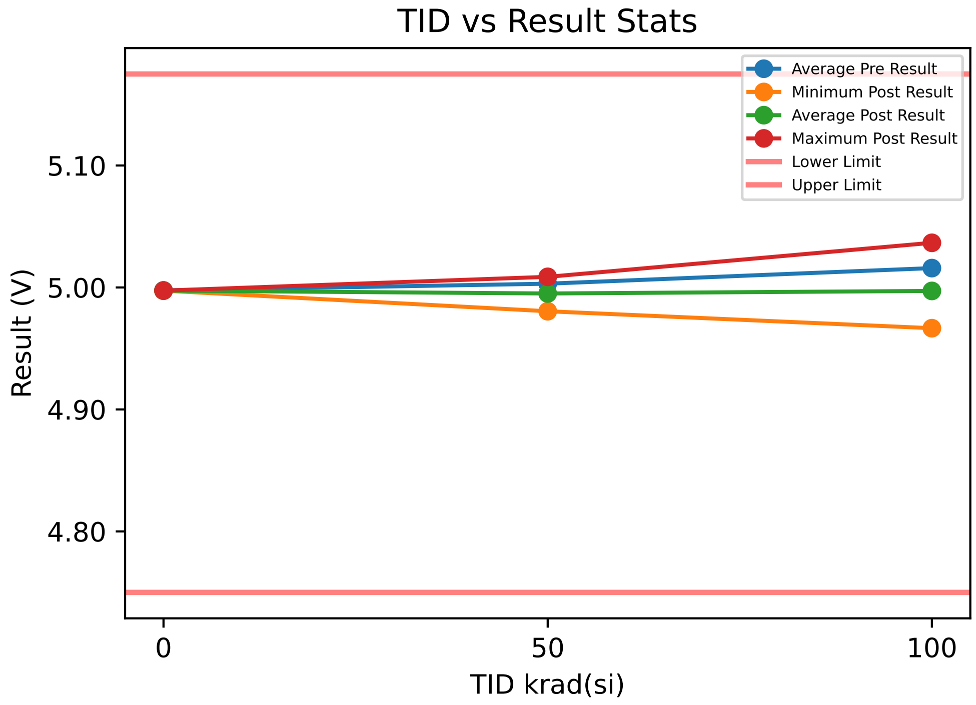
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

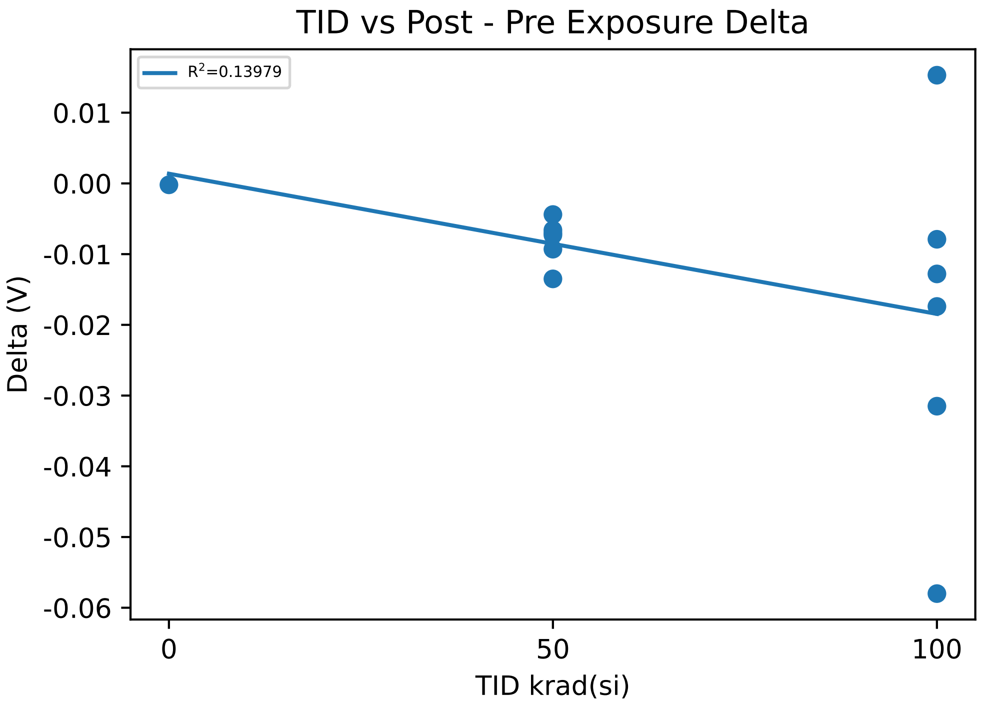
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0116	5.0107	-0.0009
60	50	Biased	4.9889	4.994	0.0051
61	50	Biased	5.0161	5.0168	0.0007
63	100	Biased	5.0107	4.9716	-0.0391
64	100	Biased	4.9954	4.9898	-0.0056
65	100	Biased	5.0106	4.974	-0.0366
66	50	Unbiased	4.9919	4.9914	-0.0005
67	50	Unbiased	4.9981	4.9966	-0.0015
68	50	Unbiased	5.0249	5.024	-0.0009
69	100	Unbiased	5.0254	5.0174	-0.008
70	100	Unbiased	4.9992	5.0025	0.0033
71	100	Unbiased	5.0134	4.9706	-0.0428
72	0	Control	5.0104	5.0132	0.0028

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0104	5.0104	5.0104		5.0132	5.0132	5.0132		0.0028	0.0028	0.0028	
50	4.9889	5.0053	5.0249	0.014428	4.9914	5.0056	5.024	0.01347	-0.0015	0.00033333	0.0051	0.0024476
100	4.9954	5.0091	5.0254	0.010721	4.9706	4.9876	5.0174	0.019209	-0.0428	-0.021467	0.0033	0.020207

Device Test: 60.23 V_BP5H IIM 5MHz VIN_10V





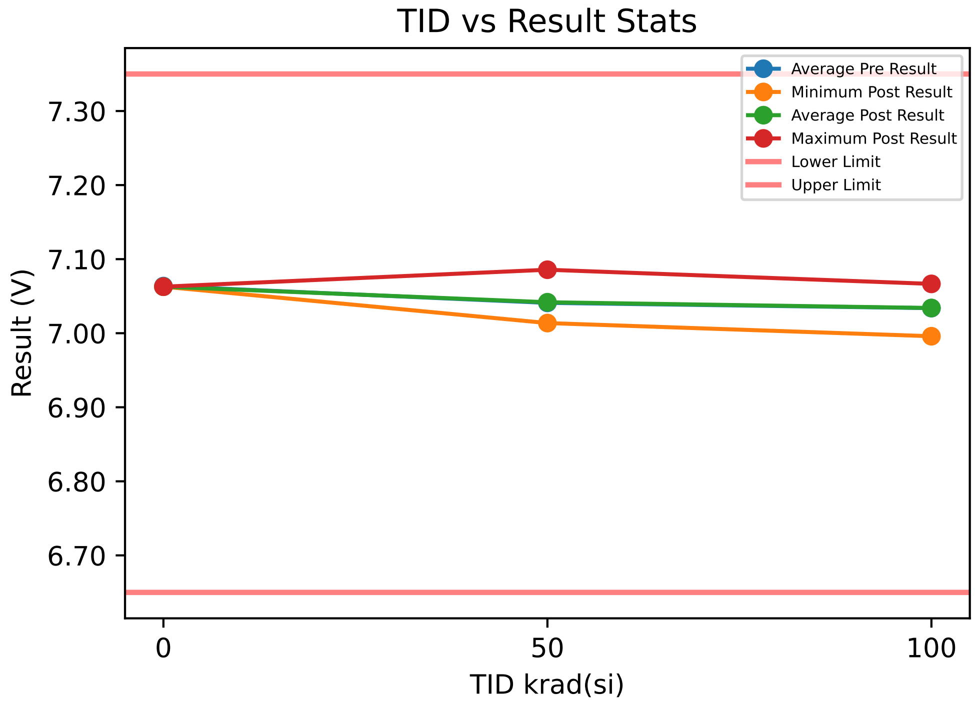
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

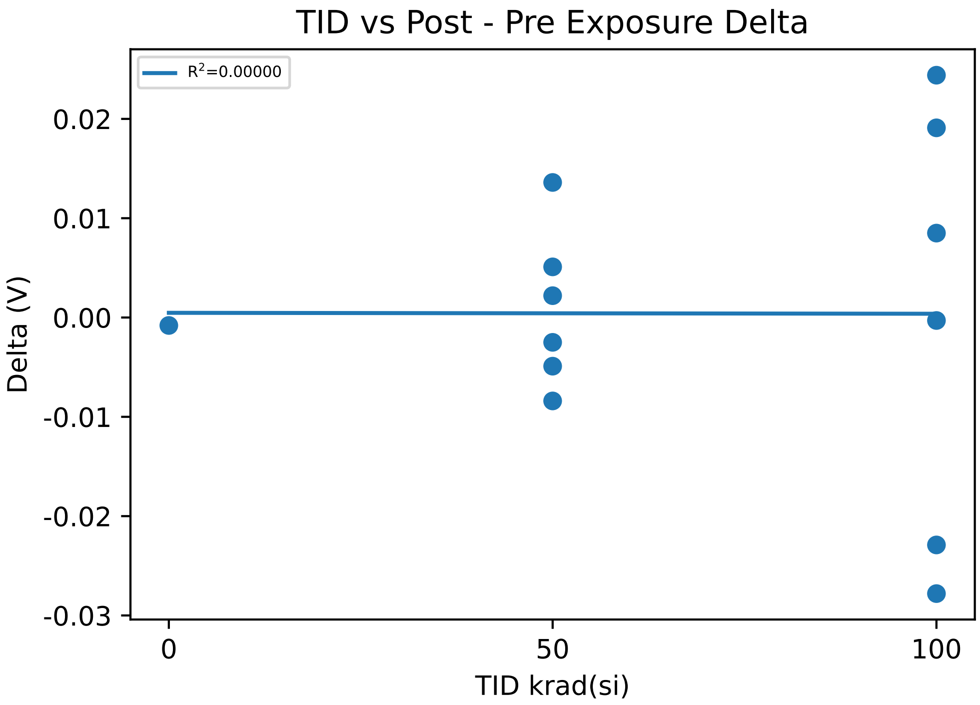
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0077	5.0011	-0.0066
60	50	Biased	4.9946	4.9876	-0.007
61	50	Biased	5.0078	5.0034	-0.0044
63	100	Biased	5.0034	4.986	-0.0174
64	100	Biased	5.0248	4.9933	-0.0315
65	100	Biased	5.0257	5.0178	-0.0079
66	50	Unbiased	4.9898	4.9805	-0.0093
67	50	Unbiased	4.9964	4.9891	-0.0073
68	50	Unbiased	5.0222	5.0087	-0.0135
69	100	Unbiased	5.0246	4.9666	-0.058
70	100	Unbiased	4.9954	4.9826	-0.0128
71	100	Unbiased	5.0213	5.0366	0.0153
72	0	Control	4.9976	4.9974	-0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9976	4.9976	4.9976		4.9974	4.9974	4.9974		-0.0002	-0.0002	-0.0002	
50	4.9898	5.0031	5.0222	0.01185	4.9805	4.9951	5.0087	0.010911	-0.0135	-0.0080167	-0.0044	0.0031096
100	4.9954	5.0159	5.0257	0.013089	4.9666	4.9972	5.0366	0.025561	-0.058	-0.018717	0.0153	0.024566

Device Test: 60.3 V_BP7L PWM 1MHz VIN_10V





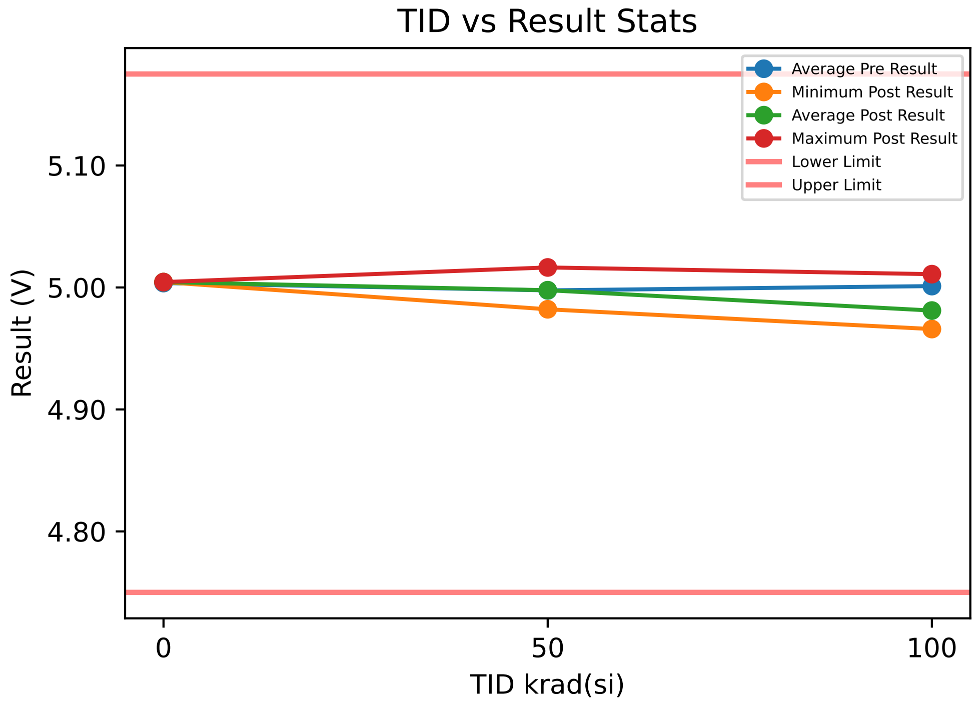
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

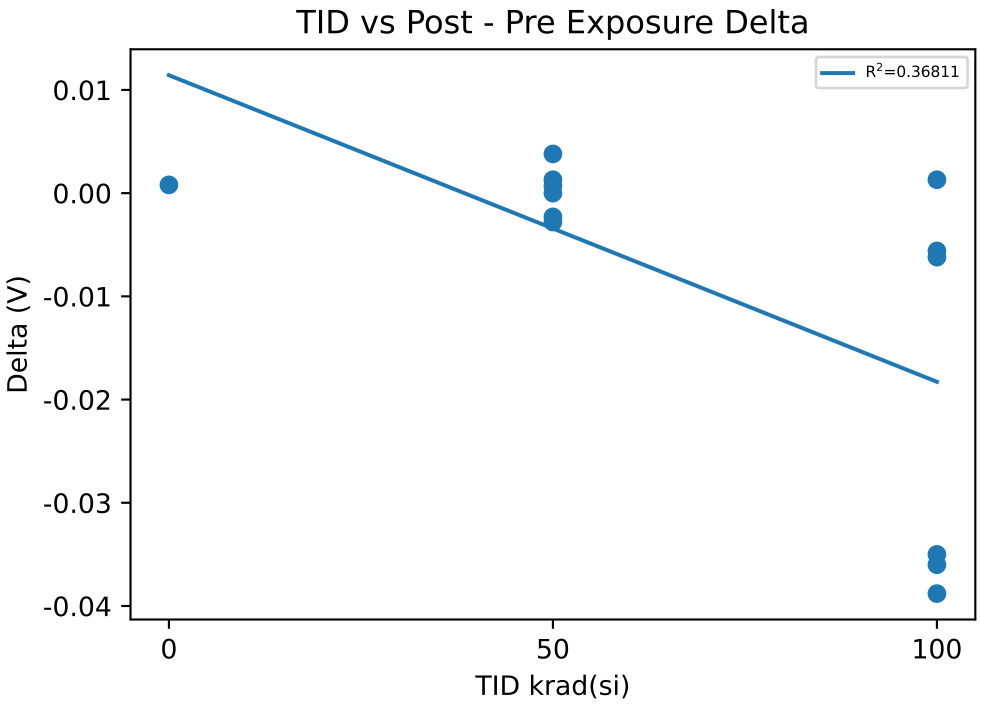
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0586	7.0537	-0.0049
60	50	Biased	7.0221	7.0137	-0.0084
61	50	Biased	7.0397	7.0419	0.0022
63	100	Biased	7.0426	7.0511	0.0085
64	100	Biased	7.0379	7.015	-0.0229
65	100	Biased	7.0669	7.0666	-0.0003
66	50	Unbiased	7.0247	7.0222	-0.0025
67	50	Unbiased	7.0201	7.0337	0.0136
68	50	Unbiased	7.0806	7.0857	0.0051
69	100	Unbiased	7.0307	7.0498	0.0191
70	100	Unbiased	6.9715	6.9959	0.0244
71	100	Unbiased	7.0536	7.0258	-0.0278
72	0	Control	7.0636	7.0628	-0.0008

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0636	7.0636	7.0636		7.0628	7.0628	7.0628		-0.0008	-0.0008	-0.0008	
50	7.0201	7.041	7.0806	0.024246	7.0137	7.0418	7.0857	0.025722	-0.0084	0.00085	0.0136	0.0079031
100	6.9715	7.0339	7.0669	0.033084	6.9959	7.034	7.0666	0.026399	-0.0278	0.00016667	0.0244	0.021585

Device Test: 60.4 V_BP5L PWM 1MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

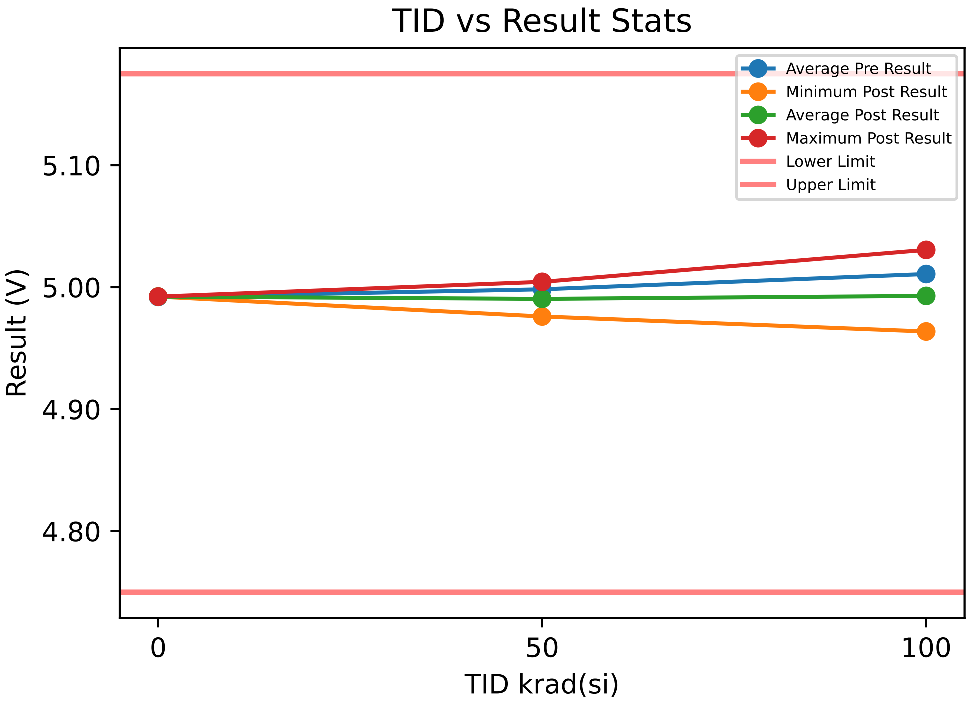
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

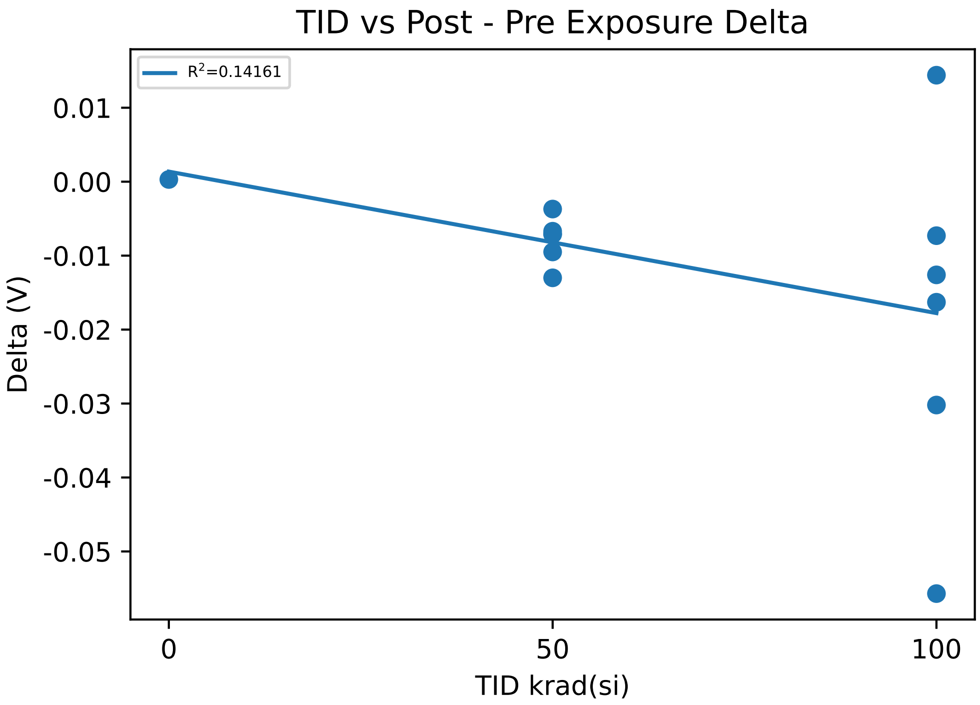
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0027	5.0027	0
60	50	Biased	4.9828	4.9866	0.0038
61	50	Biased	5.0077	5.009	0.0013
63	100	Biased	5.0024	4.9664	-0.036
64	100	Biased	4.9897	4.9835	-0.0062
65	100	Biased	5.001	4.966	-0.035
66	50	Unbiased	4.9849	4.9821	-0.0028
67	50	Unbiased	4.9889	4.9896	0.0007
68	50	Unbiased	5.0187	5.0164	-0.0023
69	100	Unbiased	5.0165	5.0109	-0.0056
70	100	Unbiased	4.9924	4.9937	0.0013
71	100	Unbiased	5.0047	4.9659	-0.0388
72	0	Control	5.0036	5.0044	0.0008

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0036	5.0036	5.0036		5.0044	5.0044	5.0044		0.0008	0.0008	0.0008	
50	4.9828	4.9976	5.0187	0.014347	4.9821	4.9977	5.0164	0.013672	-0.0028	0.00011667	0.0038	0.0024359
100	4.9897	5.0011	5.0165	0.0095652	4.9659	4.9811	5.0109	0.018589	-0.0388	-0.02005	0.0013	0.018363

Device Test: 60.5 V_BP5H PWM 1MHz VIN_10V





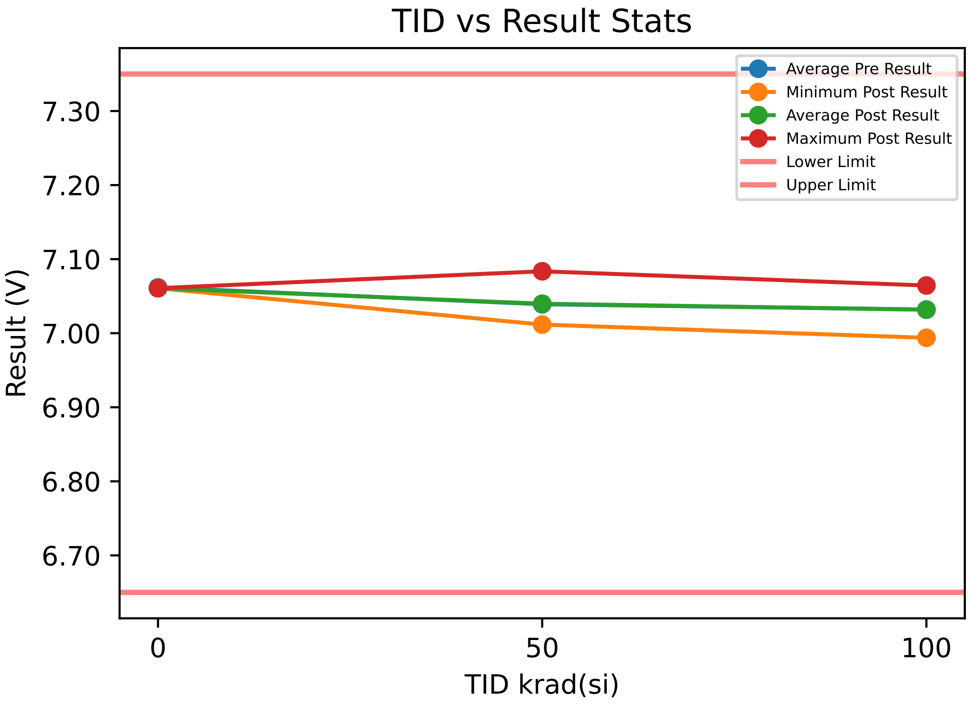
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

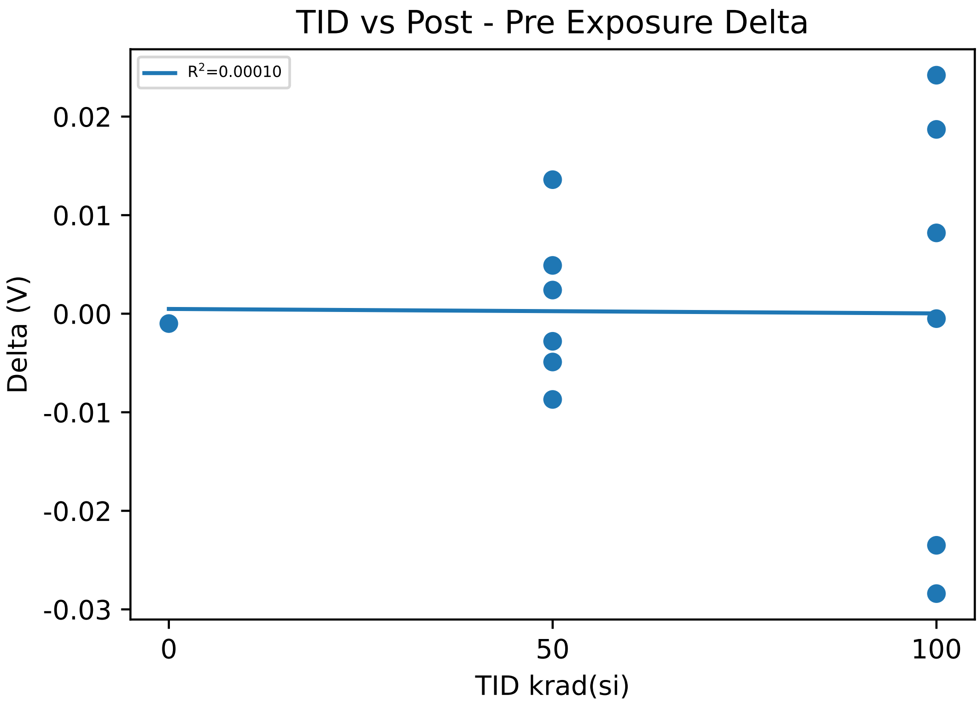
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0029	4.9962	-0.0067
60	50	Biased	4.9899	4.9828	-0.0071
61	50	Biased	5.0027	4.999	-0.0037
63	100	Biased	4.9982	4.9819	-0.0163
64	100	Biased	5.0201	4.9899	-0.0302
65	100	Biased	5.0204	5.0131	-0.0073
66	50	Unbiased	4.9855	4.976	-0.0095
67	50	Unbiased	4.9913	4.9842	-0.0071
68	50	Unbiased	5.0174	5.0044	-0.013
69	100	Unbiased	5.0194	4.9637	-0.0557
70	100	Unbiased	4.9906	4.978	-0.0126
71	100	Unbiased	5.0162	5.0306	0.0144
72	0	Control	4.992	4.9923	0.0003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.992	4.992	4.992		4.9923	4.9923	4.9923		0.0003	0.0003	0.0003	
50	4.9855	4.9983	5.0174	0.011737	4.976	4.9904	5.0044	0.01102	-0.013	-0.00785	-0.0037	0.0031278
100	4.9906	5.0108	5.0204	0.013027	4.9637	4.9929	5.0306	0.024633	-0.0557	-0.01795	0.0144	0.023522

Device Test: 60.6 V_BP7L PWM 2MHz VIN_10V





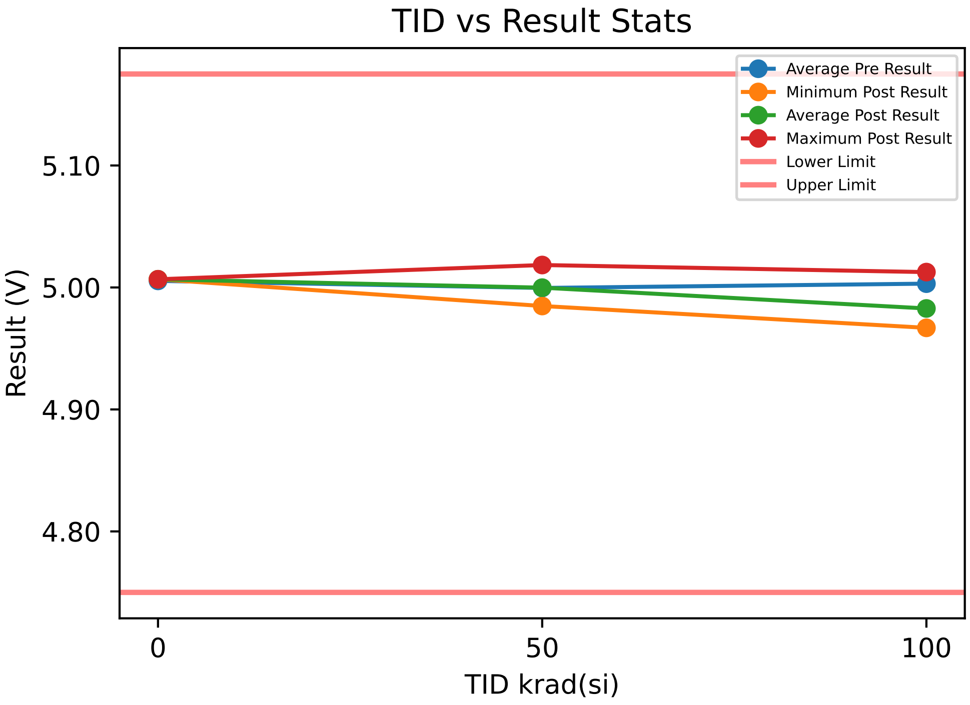
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

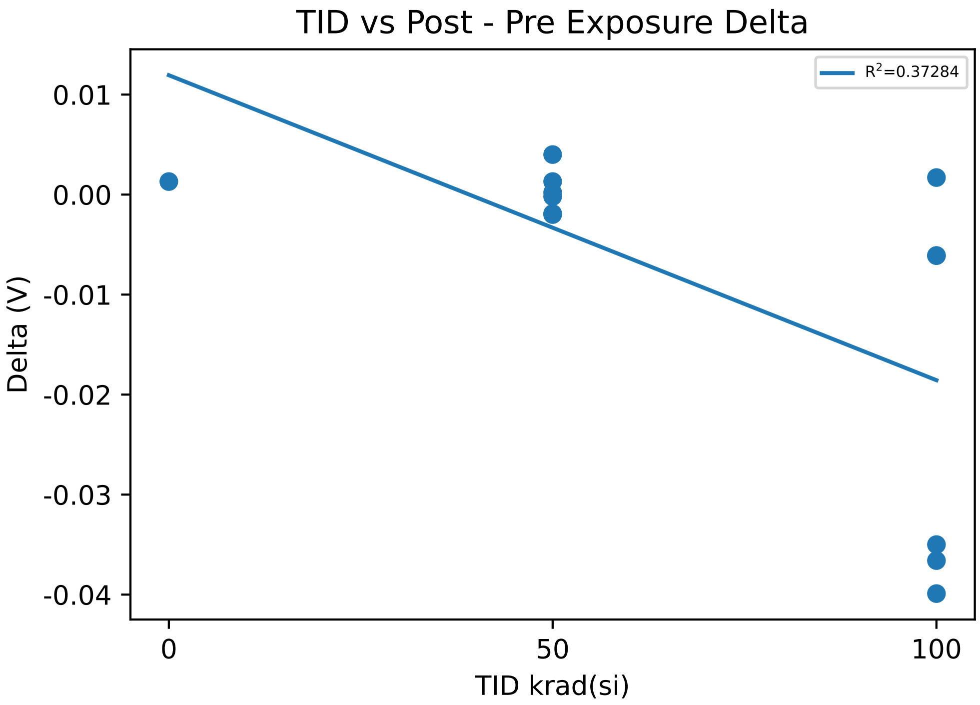
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0566	7.0517	-0.0049
60	50	Biased	7.0203	7.0116	-0.0087
61	50	Biased	7.0377	7.0401	0.0024
63	100	Biased	7.0406	7.0488	0.0082
64	100	Biased	7.0361	7.0126	-0.0235
65	100	Biased	7.0649	7.0644	-0.0005
66	50	Unbiased	7.0229	7.0201	-0.0028
67	50	Unbiased	7.0182	7.0318	0.0136
68	50	Unbiased	7.0787	7.0836	0.0049
69	100	Unbiased	7.0289	7.0476	0.0187
70	100	Unbiased	6.9696	6.9938	0.0242
71	100	Unbiased	7.0516	7.0232	-0.0284
72	0	Control	7.0618	7.0608	-0.001

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0618	7.0618	7.0618		7.0608	7.0608	7.0608		-0.001	-0.001	-0.001	
50	7.0182	7.0391	7.0787	0.024204	7.0116	7.0398	7.0836	0.02572	-0.0087	0.00075	0.0136	0.0079862
100	6.9696	7.0319	7.0649	0.033048	6.9938	7.0317	7.0644	0.026412	-0.0284	-0.00021667	0.0242	0.021732

Device Test: 60.7 V_BP5L PWM 2MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

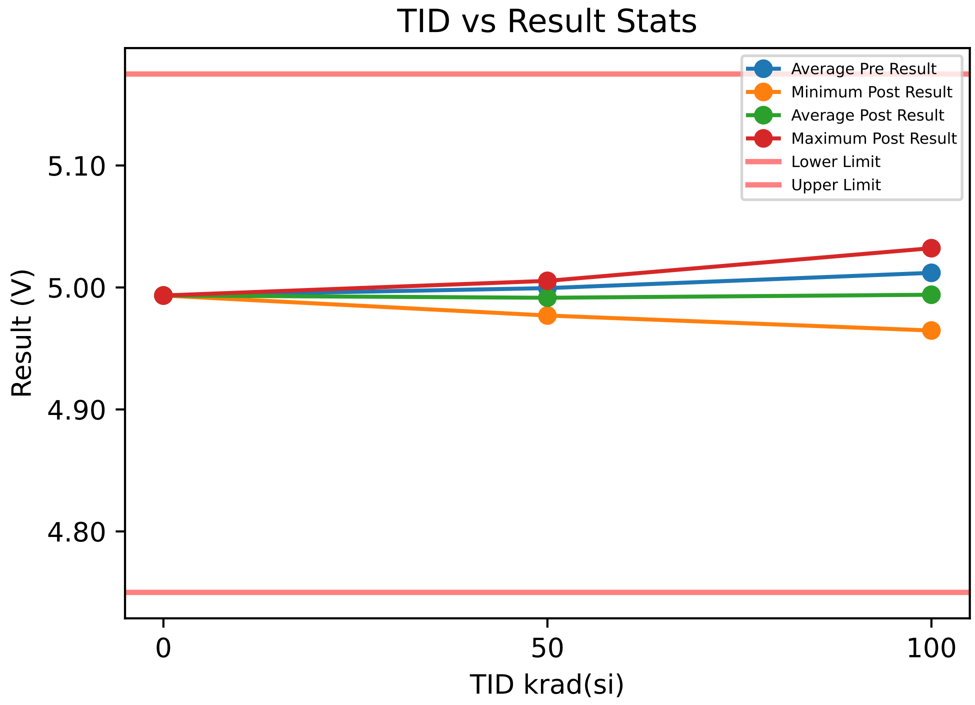
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

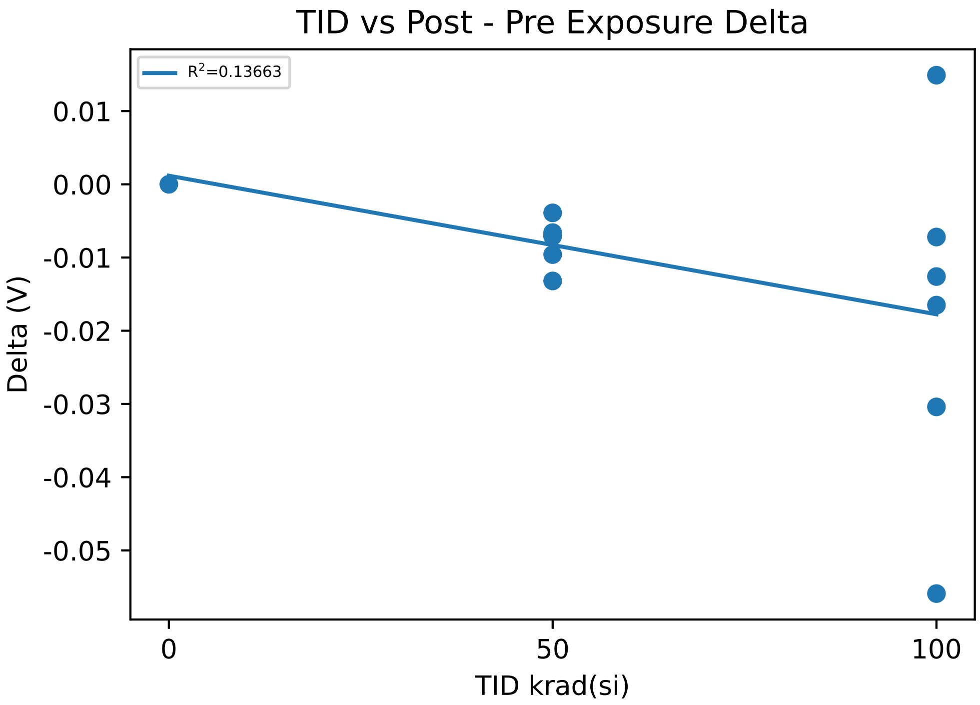
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.005	5.0048	-0.0002
60	50	Biased	4.9845	4.9885	0.004
61	50	Biased	5.0098	5.0111	0.0013
63	100	Biased	5.0045	4.9679	-0.0366
64	100	Biased	4.9913	4.9852	-0.0061
65	100	Biased	5.0033	4.9683	-0.035
66	50	Unbiased	4.9867	4.9848	-0.0019
67	50	Unbiased	4.9912	4.9914	0.0002
68	50	Unbiased	5.0204	5.0184	-0.002
69	100	Unbiased	5.0187	5.0126	-0.0061
70	100	Unbiased	4.9941	4.9958	0.0017
71	100	Unbiased	5.0068	4.9669	-0.0399
72	0	Control	5.0054	5.0067	0.0013

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0054	5.0054	5.0054		5.0067	5.0067	5.0067		0.0013	0.0013	0.0013	
50	4.9845	4.9996	5.0204	0.014358	4.9848	4.9998	5.0184	0.013579	-0.002	0.00023333	0.004	0.0022385
100	4.9913	5.0031	5.0187	0.0097907	4.9669	4.9828	5.0126	0.018697	-0.0399	-0.020333	0.0017	0.018725

Device Test: 60.8 V_BP5H PWM 2MHz VIN_10V





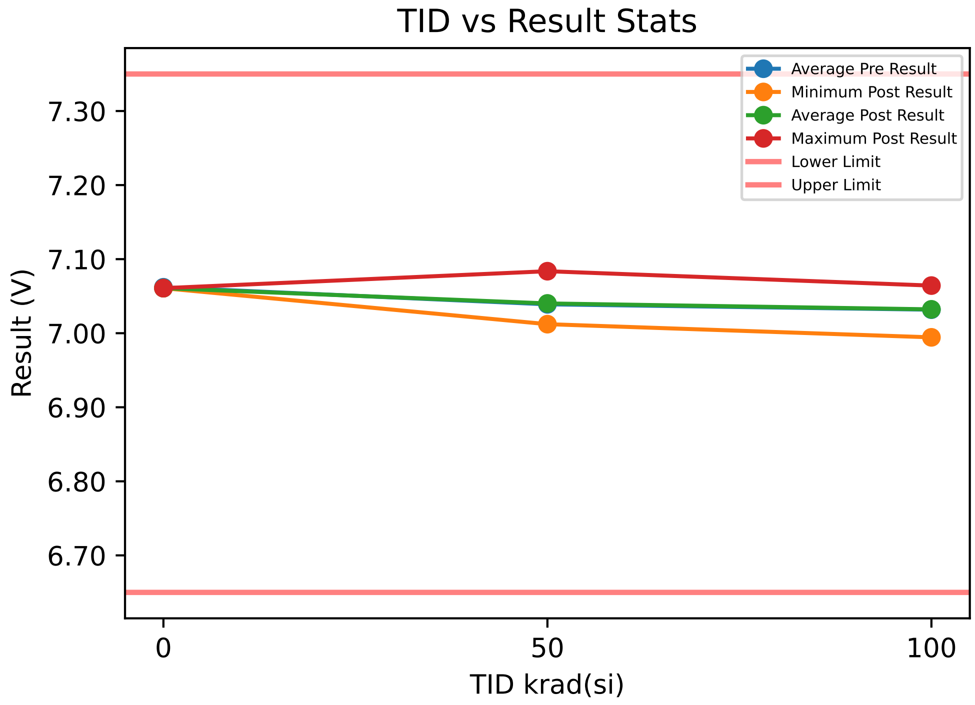
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

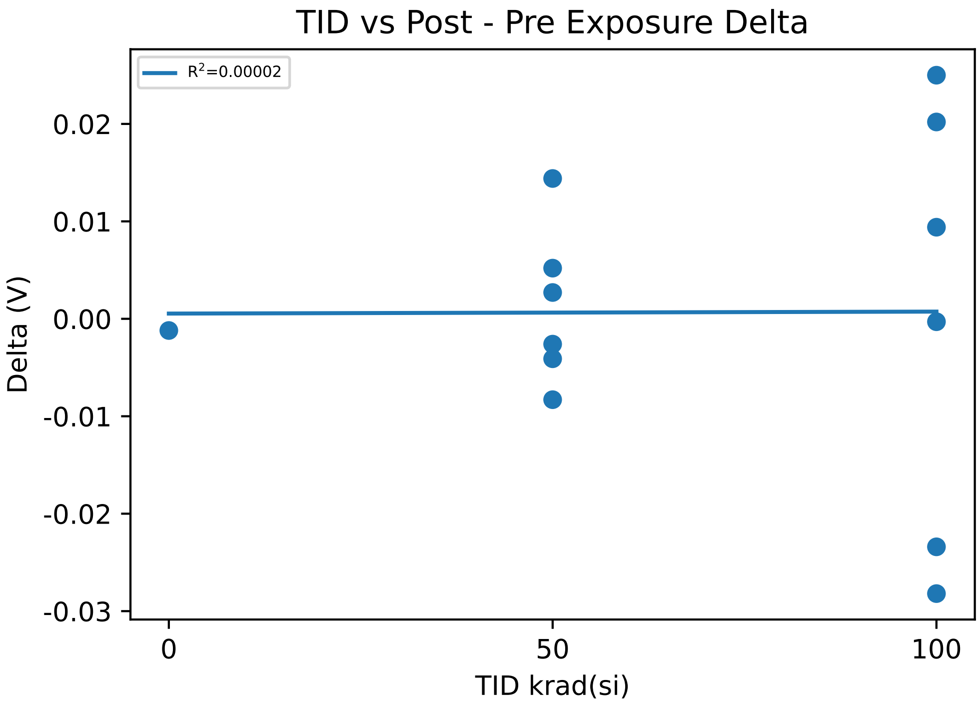
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.004	4.9974	-0.0066
60	50	Biased	4.991	4.9839	-0.0071
61	50	Biased	5.004	5.0001	-0.0039
63	100	Biased	4.9994	4.9829	-0.0165
64	100	Biased	5.0213	4.9909	-0.0304
65	100	Biased	5.0215	5.0143	-0.0072
66	50	Unbiased	4.9866	4.977	-0.0096
67	50	Unbiased	4.9925	4.9855	-0.007
68	50	Unbiased	5.0186	5.0054	-0.0132
69	100	Unbiased	5.0206	4.9647	-0.0559
70	100	Unbiased	4.9918	4.9792	-0.0126
71	100	Unbiased	5.0173	5.0322	0.0149
72	0	Control	4.9934	4.9934	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9934	4.9934	4.9934		4.9934	4.9934	4.9934		0	0	0	
50	4.9866	4.9994	5.0186	0.011772	4.977	4.9916	5.0054	0.011009	-0.0132	-0.0079	-0.0039	0.0031661
100	4.9918	5.012	5.0215	0.013005	4.9647	4.994	5.0322	0.024826	-0.0559	-0.01795	0.0149	0.023751

Device Test: 60.9 V_BP7L PWM 5MHz VIN_10V





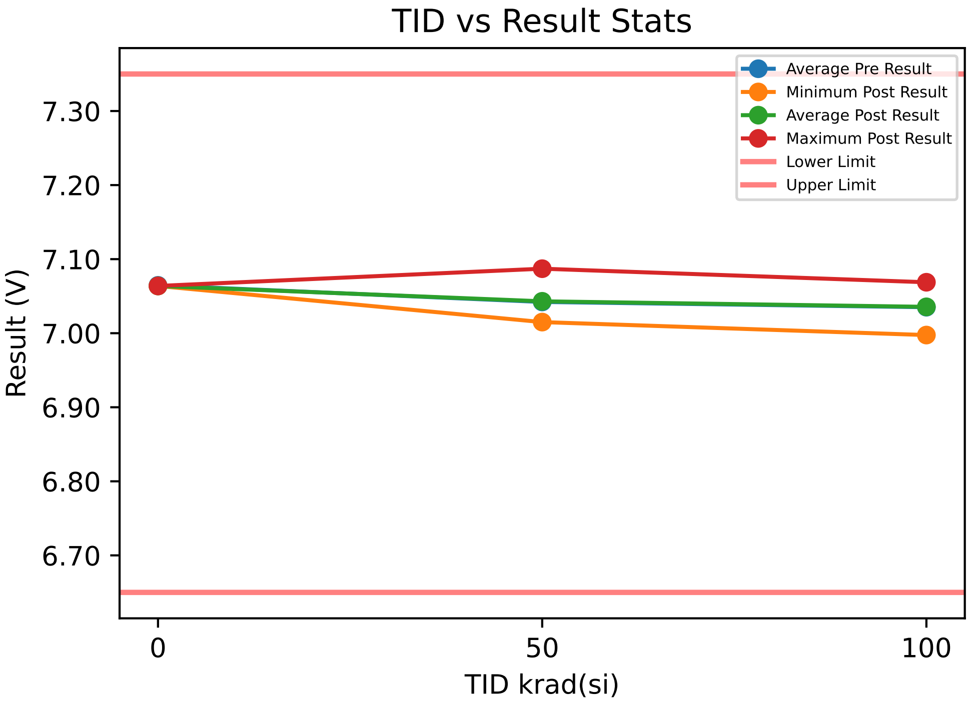
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

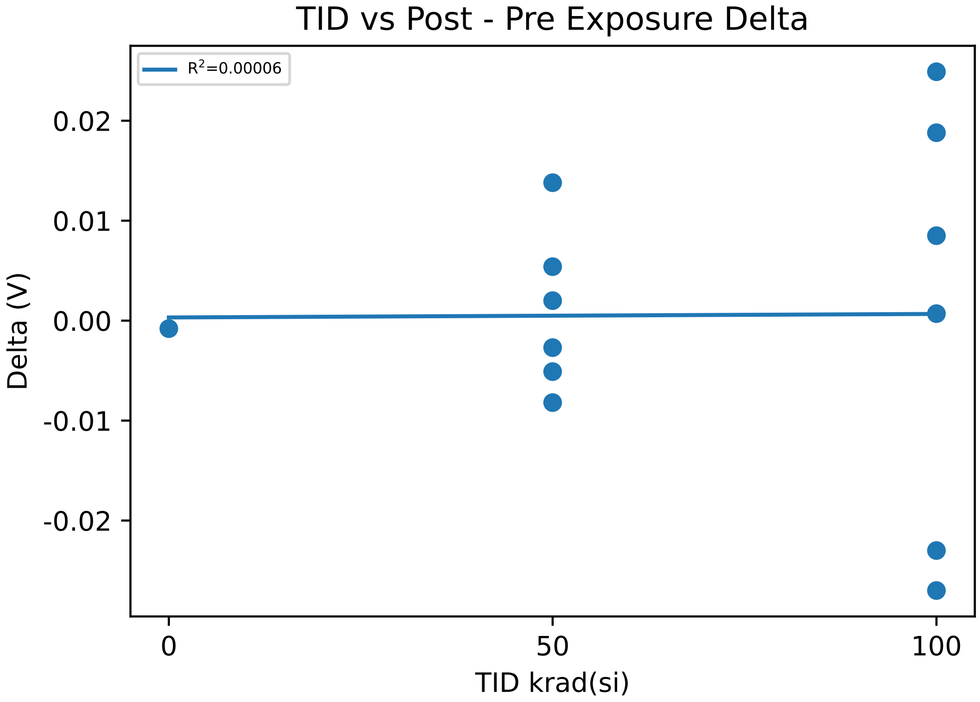
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0564	7.0523	-0.0041
60	50	Biased	7.0205	7.0122	-0.0083
61	50	Biased	7.0377	7.0404	0.0027
63	100	Biased	7.0403	7.0497	0.0094
64	100	Biased	7.0366	7.0132	-0.0234
65	100	Biased	7.0646	7.0643	-0.0003
66	50	Unbiased	7.0229	7.0203	-0.0026
67	50	Unbiased	7.0179	7.0323	0.0144
68	50	Unbiased	7.0785	7.0837	0.0052
69	100	Unbiased	7.0284	7.0486	0.0202
70	100	Unbiased	6.9694	6.9944	0.025
71	100	Unbiased	7.0513	7.0231	-0.0282
72	0	Control	7.062	7.0608	-0.0012

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.062	7.062	7.062		7.0608	7.0608	7.0608		-0.0012	-0.0012	-0.0012	
50	7.0179	7.039	7.0785	0.02413	7.0122	7.0402	7.0837	0.025617	-0.0083	0.0012167	0.0144	0.0080656
100	6.9694	7.0318	7.0646	0.033035	6.9944	7.0322	7.0643	0.026375	-0.0282	0.00045	0.025	0.022195

Device Test: 61.0 V_BP7L PWM 500kHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

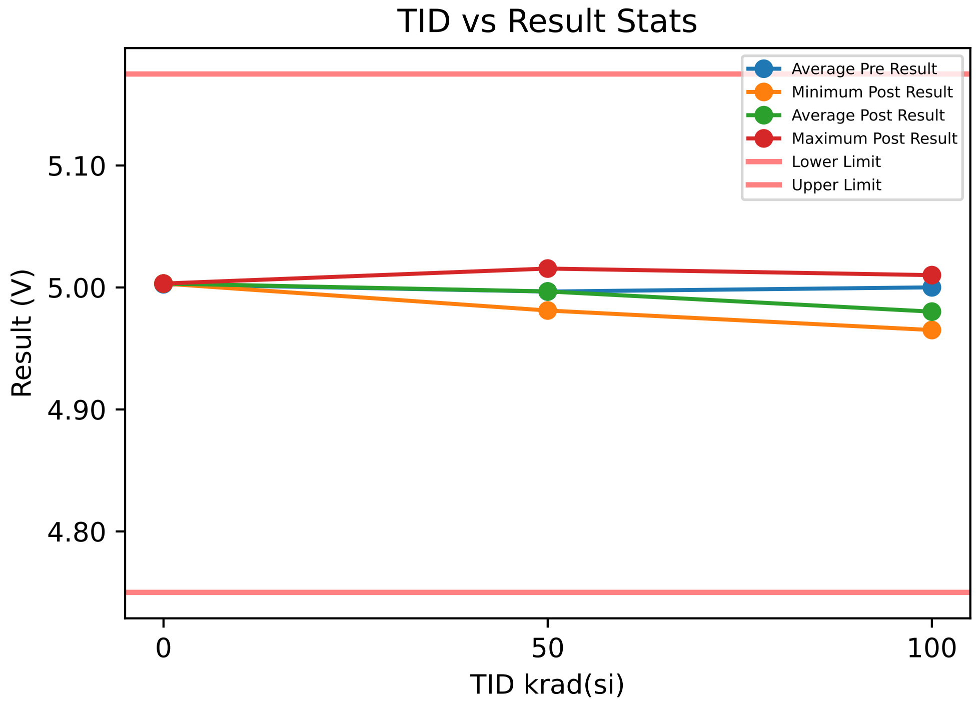
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.06	7.0549	-0.0051
60	50	Biased	7.0232	7.015	-0.0082
61	50	Biased	7.041	7.043	0.002
63	100	Biased	7.0437	7.0522	0.0085
64	100	Biased	7.0392	7.0162	-0.023
65	100	Biased	7.0681	7.0688	0.0007
66	50	Unbiased	7.026	7.0233	-0.0027
67	50	Unbiased	7.0213	7.0351	0.0138
68	50	Unbiased	7.0817	7.0871	0.0054
69	100	Unbiased	7.0321	7.0509	0.0188
70	100	Unbiased	6.9726	6.9975	0.0249
71	100	Unbiased	7.055	7.028	-0.027
72	0	Control	7.0646	7.0638	-0.0008

Test Statistics (V)

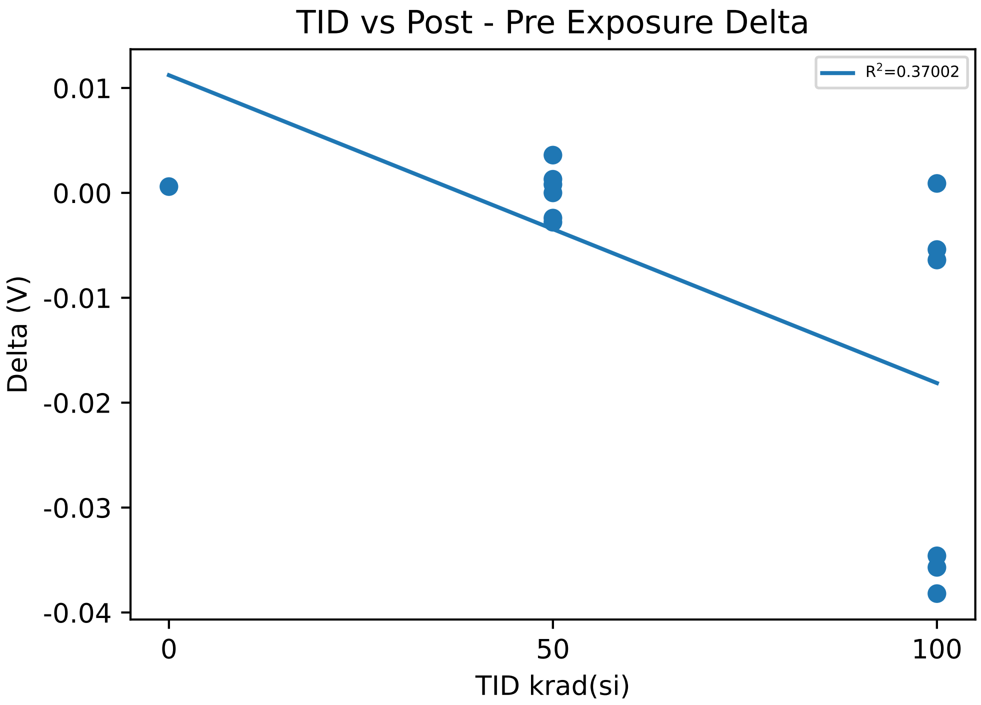
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0646	7.0646	7.0646		7.0638	7.0638	7.0638		-0.0008	-0.0008	-0.0008	
50	7.0213	7.0422	7.0817	0.024244	7.015	7.0431	7.0871	0.025772	-0.0082	0.00086667	0.0138	0.0079954
100	6.9726	7.0351	7.0681	0.033139	6.9975	7.0356	7.0688	0.026449	-0.027	0.00048333	0.0249	0.021461

Device Test: 61.1 V_BP5L PWM 500kHz VIN_12V


TID vs Result Stats

Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

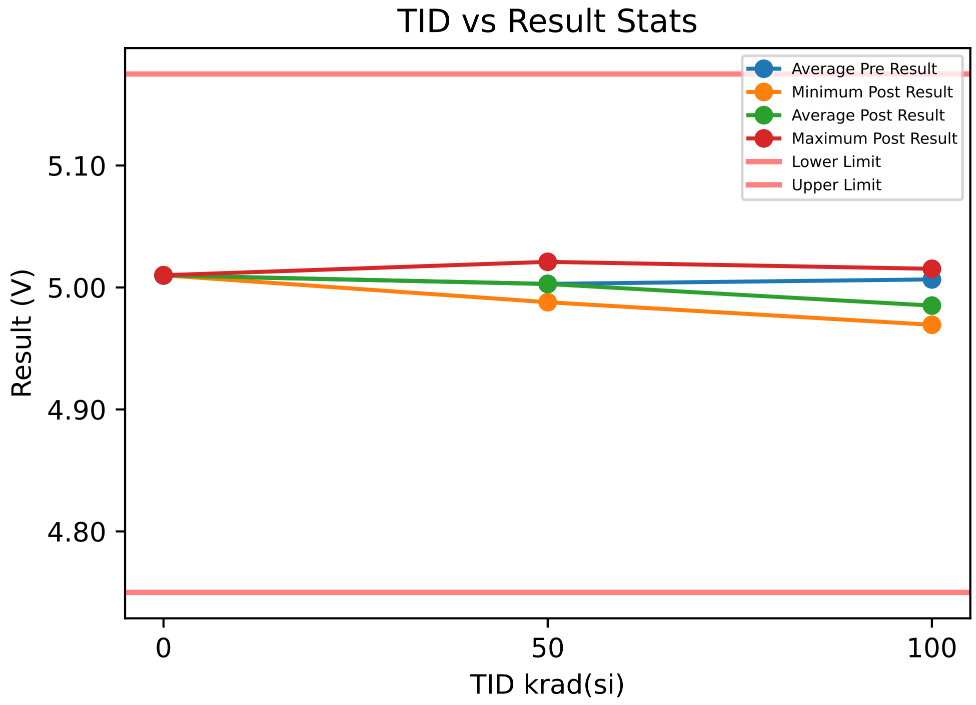
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0016	5.0016	0
60	50	Biased	4.982	4.9856	0.0036
61	50	Biased	5.0067	5.008	0.0013
63	100	Biased	5.0015	4.9658	-0.0357
64	100	Biased	4.9889	4.9825	-0.0064
65	100	Biased	4.9997	4.9651	-0.0346
66	50	Unbiased	4.9839	4.9811	-0.0028
67	50	Unbiased	4.9878	4.9886	0.0008
68	50	Unbiased	5.0179	5.0155	-0.0024
69	100	Unbiased	5.0155	5.0101	-0.0054
70	100	Unbiased	4.9914	4.9923	0.0009
71	100	Unbiased	5.0035	4.9653	-0.0382
72	0	Control	5.0026	5.0032	0.0006

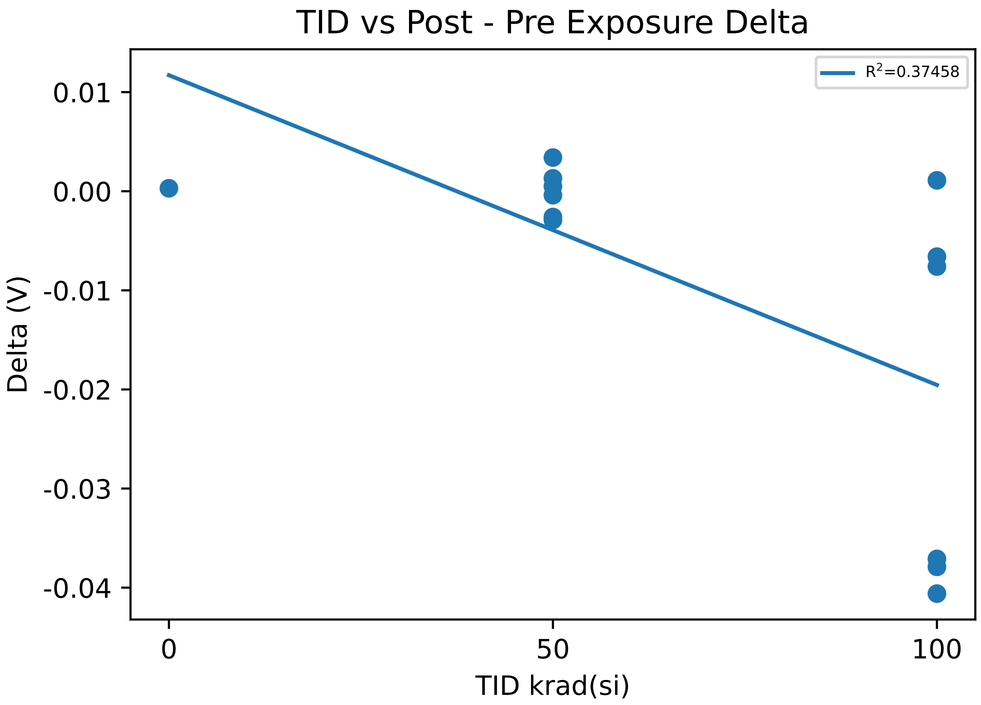

TID vs Post - Pre Exposure Delta

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0026	5.0026	5.0026		5.0032	5.0032	5.0032		0.0006	0.0006	0.0006	
50	4.982	4.9966	5.0179	0.014371	4.9811	4.9967	5.0155	0.013692	-0.0028	8.3333e-05	0.0036	0.002402
100	4.9889	5.0001	5.0155	0.0095076	4.9651	4.9802	5.0101	0.018456	-0.0382	-0.0199	0.0009	0.018032

Device Test: 61.10 V_BP5L PWM 5MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

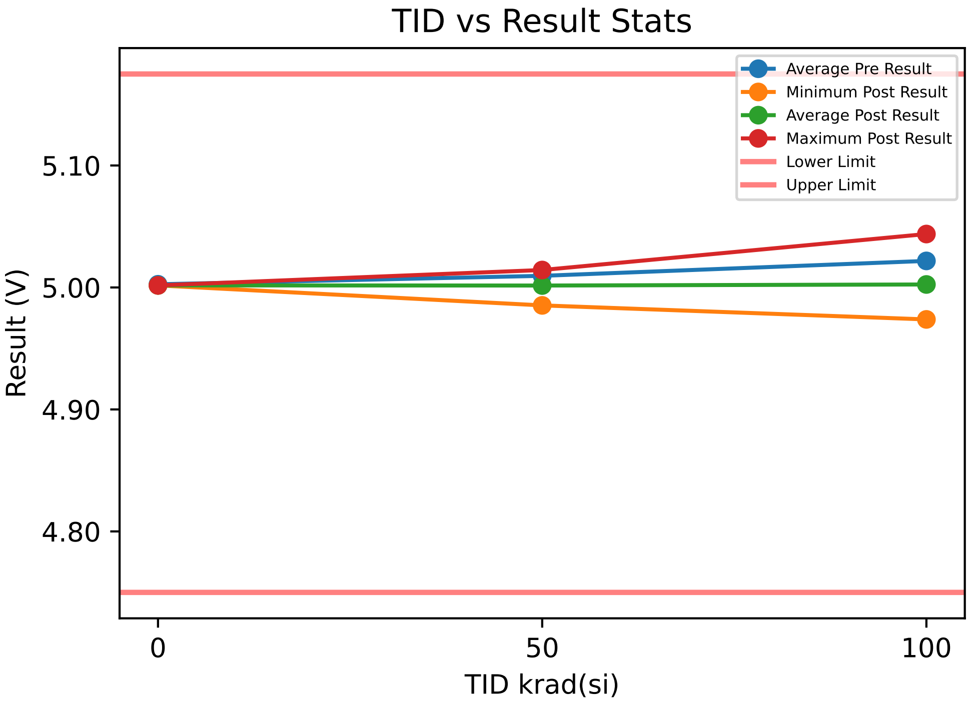
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

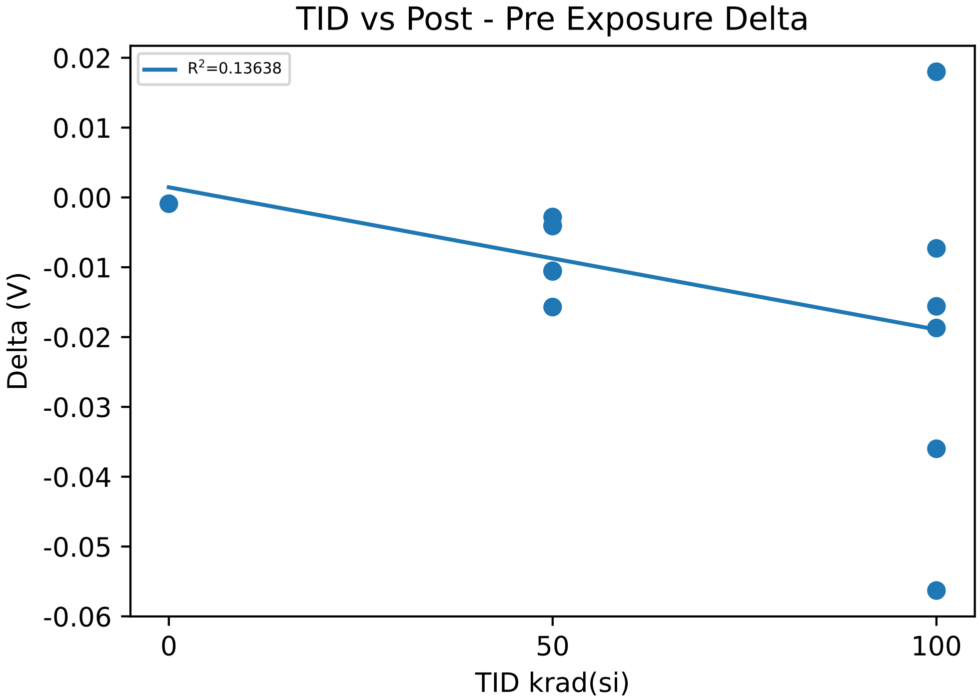
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0078	5.0074	-0.0004
60	50	Biased	4.988	4.9914	0.0034
61	50	Biased	5.0131	5.0144	0.0013
63	100	Biased	5.0076	4.9697	-0.0379
64	100	Biased	4.9954	4.9878	-0.0076
65	100	Biased	5.0065	4.9694	-0.0371
66	50	Unbiased	4.9905	4.9879	-0.0026
67	50	Unbiased	4.9943	4.9948	0.0005
68	50	Unbiased	5.0239	5.021	-0.0029
69	100	Unbiased	5.0219	5.0153	-0.0066
70	100	Unbiased	4.998	4.9991	0.0011
71	100	Unbiased	5.0101	4.9695	-0.0406
72	0	Control	5.0097	5.01	0.0003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0097	5.0097	5.0097		5.01	5.01	5.01		0.0003	0.0003	0.0003	
50	4.988	5.0029	5.0239	0.014274	4.9879	5.0028	5.021	0.013438	-0.0029	-0.00011667	0.0034	0.0023978
100	4.9954	5.0066	5.0219	0.0094525	4.9694	4.9851	5.0153	0.019195	-0.0406	-0.02145	0.0011	0.01899

Device Test: 61.11 V_BP5H PWM 5MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

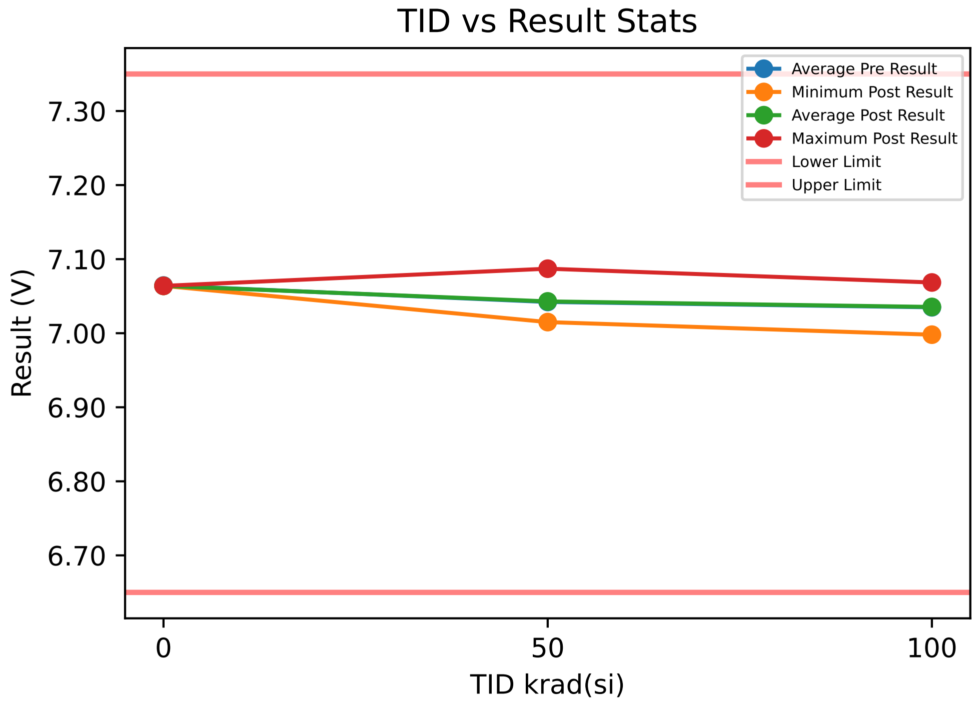
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

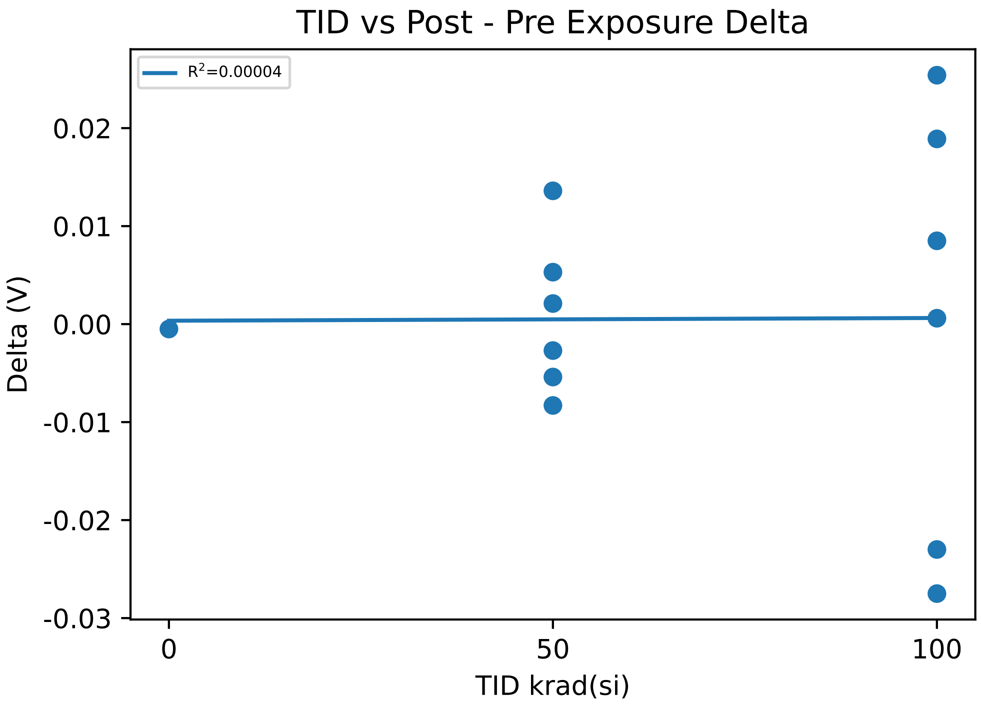
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0133	5.0092	-0.0041
60	50	Biased	5.0029	4.9924	-0.0105
61	50	Biased	5.0144	5.0116	-0.0028
63	100	Biased	5.0084	4.9897	-0.0187
64	100	Biased	5.0331	4.9971	-0.036
65	100	Biased	5.0299	5.0226	-0.0073
66	50	Unbiased	4.9959	4.9853	-0.0106
67	50	Unbiased	5.0007	4.9967	-0.004
68	50	Unbiased	5.03	5.0143	-0.0157
69	100	Unbiased	5.0301	4.9738	-0.0563
70	100	Unbiased	5.0033	4.9877	-0.0156
71	100	Unbiased	5.0258	5.0438	0.018
72	0	Control	5.0026	5.0017	-0.0009

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0026	5.0026	5.0026		5.0017	5.0017	5.0017		-0.0009	-0.0009	-0.0009	
50	4.9959	5.0095	5.03	0.012367	4.9853	5.0016	5.0143	0.011776	-0.0157	-0.00795	-0.0028	0.0051095
100	5.0033	5.0218	5.0331	0.012649	4.9738	5.0024	5.0438	0.025867	-0.0563	-0.019317	0.018	0.025287

Device Test: 61.12 V_BP7L IIM 500kHz VIN_12V





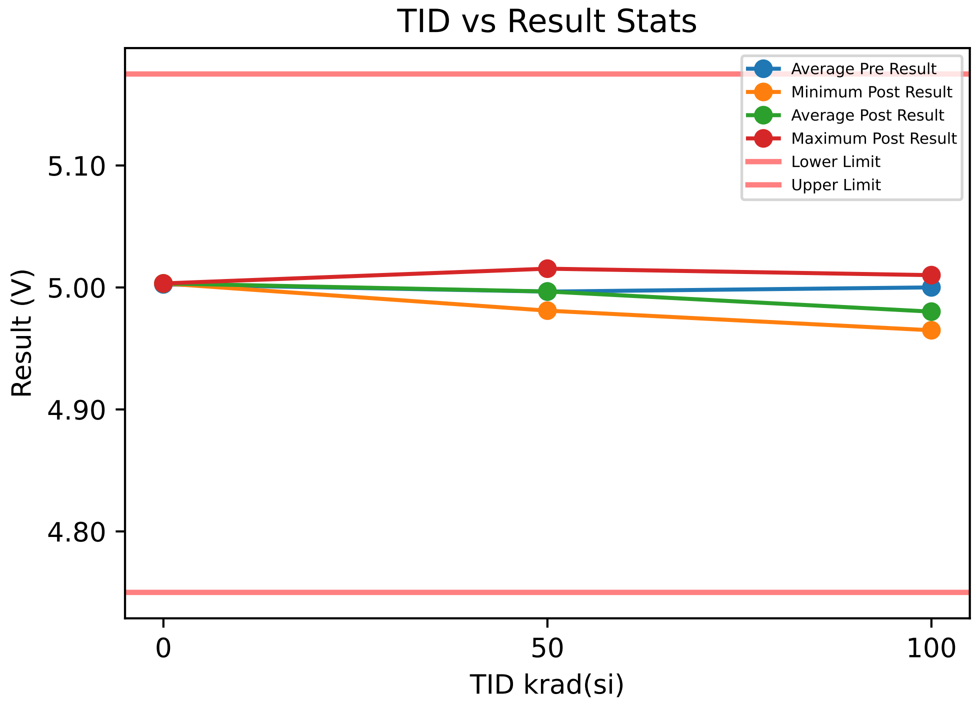
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

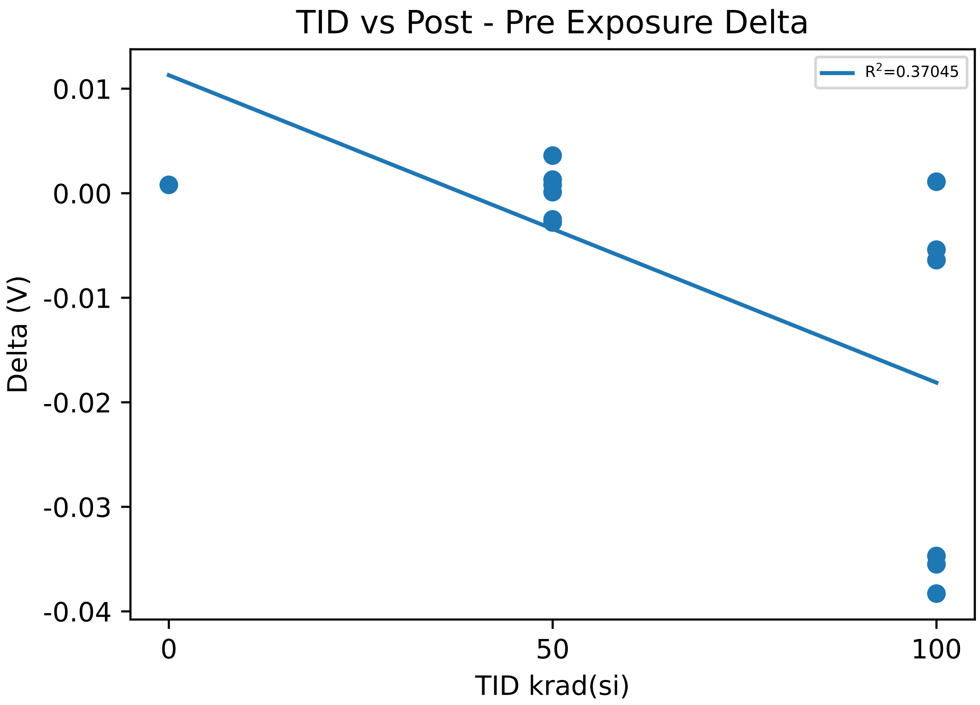
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0599	7.0545	-0.0054
60	50	Biased	7.0233	7.015	-0.0083
61	50	Biased	7.0409	7.043	0.0021
63	100	Biased	7.0436	7.0521	0.0085
64	100	Biased	7.0391	7.0161	-0.023
65	100	Biased	7.0679	7.0685	0.0006
66	50	Unbiased	7.0258	7.0231	-0.0027
67	50	Unbiased	7.0214	7.035	0.0136
68	50	Unbiased	7.0818	7.0871	0.0053
69	100	Unbiased	7.032	7.0509	0.0189
70	100	Unbiased	6.9726	6.998	0.0254
71	100	Unbiased	7.0547	7.0272	-0.0275
72	0	Control	7.0644	7.0639	-0.0005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0644	7.0644	7.0644		7.0639	7.0639	7.0639		-0.0005	-0.0005	-0.0005	
50	7.0214	7.0422	7.0818	0.024257	7.015	7.043	7.0871	0.025772	-0.0083	0.00076667	0.0136	0.0079909
100	6.9726	7.035	7.0679	0.033058	6.998	7.0355	7.0685	0.02628	-0.0275	0.00048333	0.0254	0.02172

Device Test: 61.13 V_BP5L IIM 500kHz VIN_12V





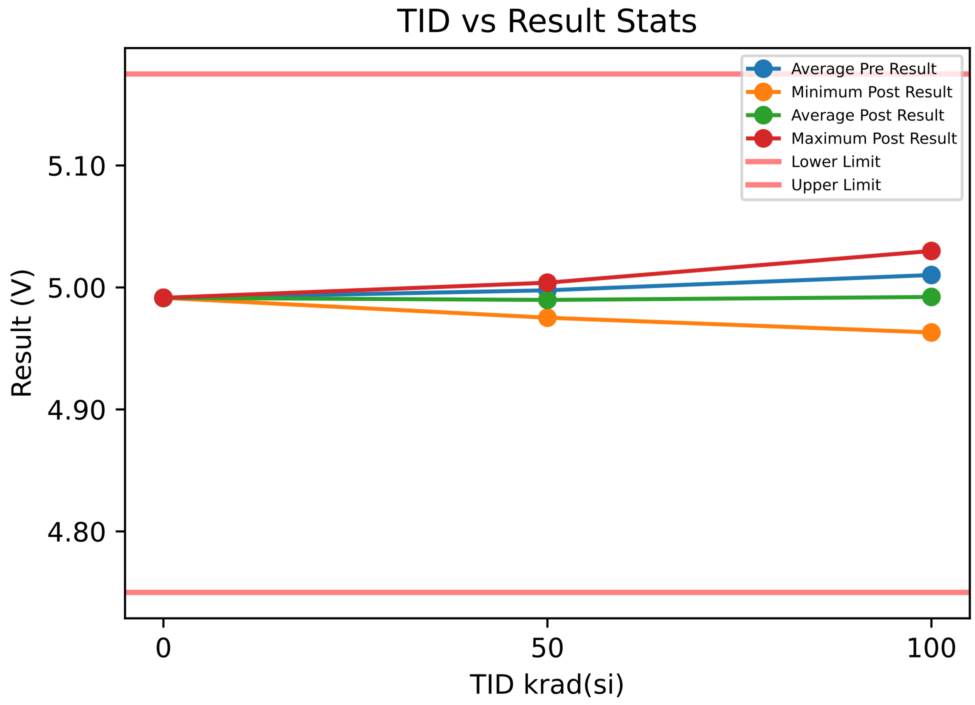
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

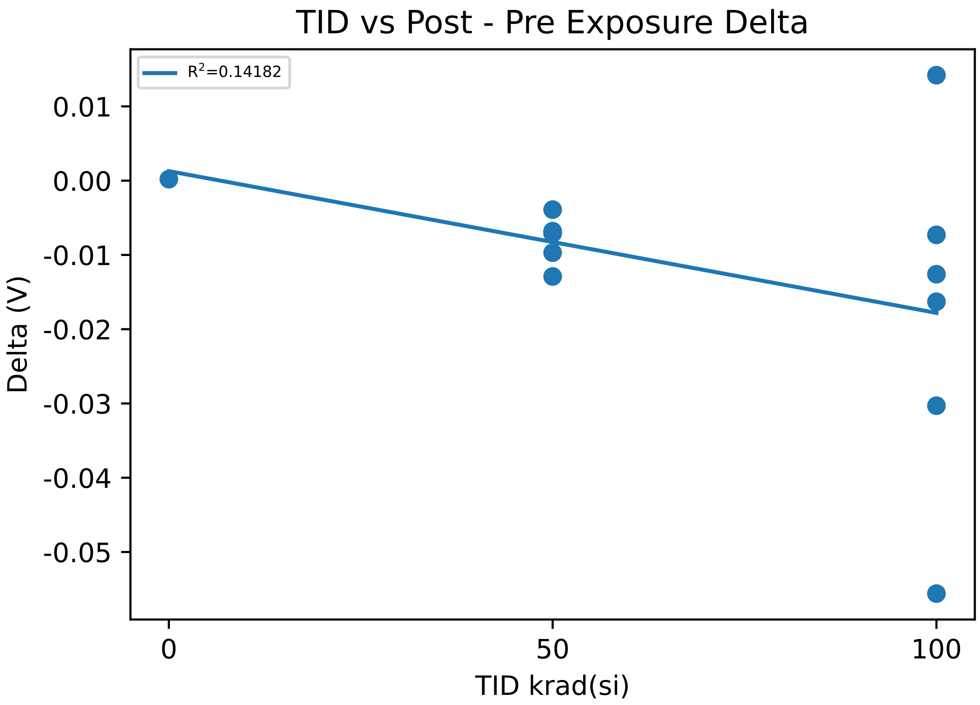
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0015	5.0016	0.0001
60	50	Biased	4.982	4.9856	0.0036
61	50	Biased	5.0067	5.008	0.0013
63	100	Biased	5.0015	4.966	-0.0355
64	100	Biased	4.9889	4.9825	-0.0064
65	100	Biased	4.9996	4.9649	-0.0347
66	50	Unbiased	4.9838	4.981	-0.0028
67	50	Unbiased	4.9878	4.9886	0.0008
68	50	Unbiased	5.0179	5.0154	-0.0025
69	100	Unbiased	5.0155	5.0101	-0.0054
70	100	Unbiased	4.9913	4.9924	0.0011
71	100	Unbiased	5.0035	4.9652	-0.0383
72	0	Control	5.0025	5.0033	0.0008

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0025	5.0025	5.0025		5.0033	5.0033	5.0033		0.0008	0.0008	0.0008	
50	4.982	4.9966	5.0179	0.014382	4.981	4.9967	5.0154	0.013687	-0.0028	8.3333e-05	0.0036	0.0024227
100	4.9889	5	5.0155	0.0095268	4.9649	4.9802	5.0101	0.018487	-0.0383	-0.019867	0.0011	0.01808

Device Test: 61.14 V_BP5H IIM 500kHz VIN_12V





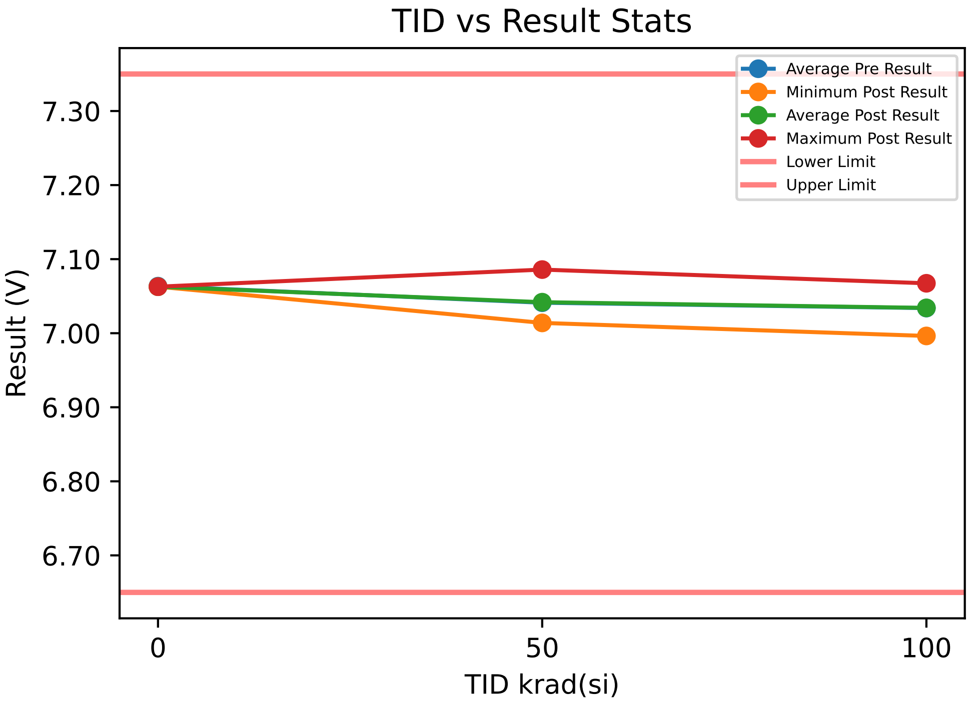
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

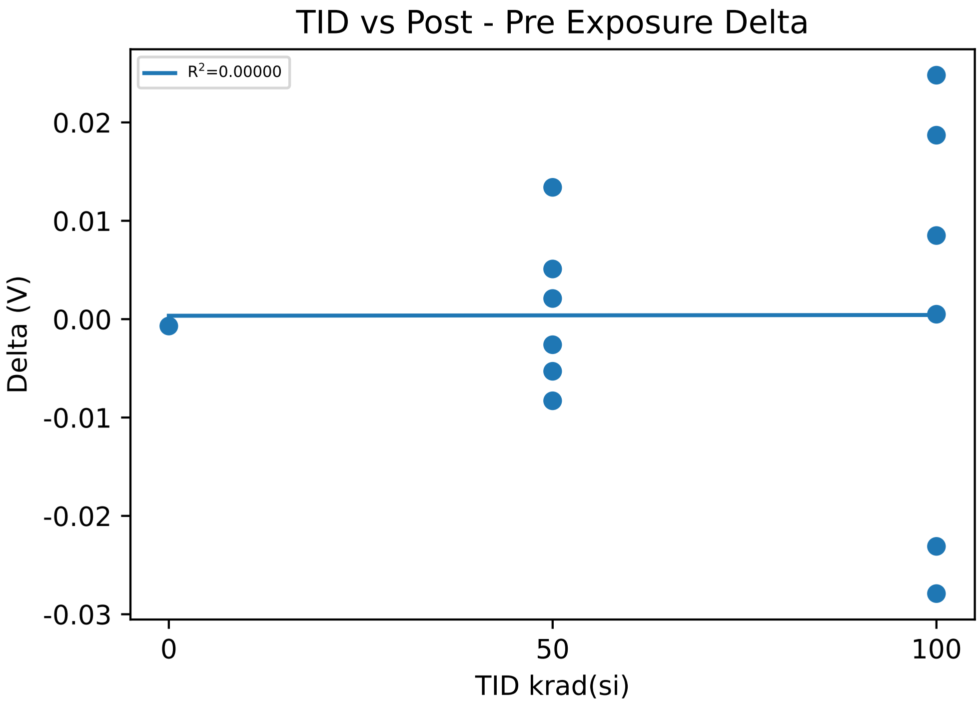
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0023	4.9955	-0.0068
60	50	Biased	4.9892	4.9822	-0.007
61	50	Biased	5.0021	4.9982	-0.0039
63	100	Biased	4.9975	4.9812	-0.0163
64	100	Biased	5.0196	4.9893	-0.0303
65	100	Biased	5.0199	5.0126	-0.0073
66	50	Unbiased	4.9849	4.9752	-0.0097
67	50	Unbiased	4.9907	4.9836	-0.0071
68	50	Unbiased	5.0168	5.0039	-0.0129
69	100	Unbiased	5.0187	4.9631	-0.0556
70	100	Unbiased	4.9898	4.9772	-0.0126
71	100	Unbiased	5.0157	5.0299	0.0142
72	0	Control	4.9913	4.9915	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9913	4.9913	4.9913		4.9915	4.9915	4.9915		0.0002	0.0002	0.0002	
50	4.9849	4.9977	5.0168	0.011751	4.9752	4.9898	5.0039	0.011056	-0.0129	-0.0079	-0.0039	0.0030627
100	4.9898	5.0102	5.0199	0.013133	4.9631	4.9922	5.0299	0.024652	-0.0556	-0.017983	0.0142	0.023445

Device Test: 61.15 V_BP7L IIM 1MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

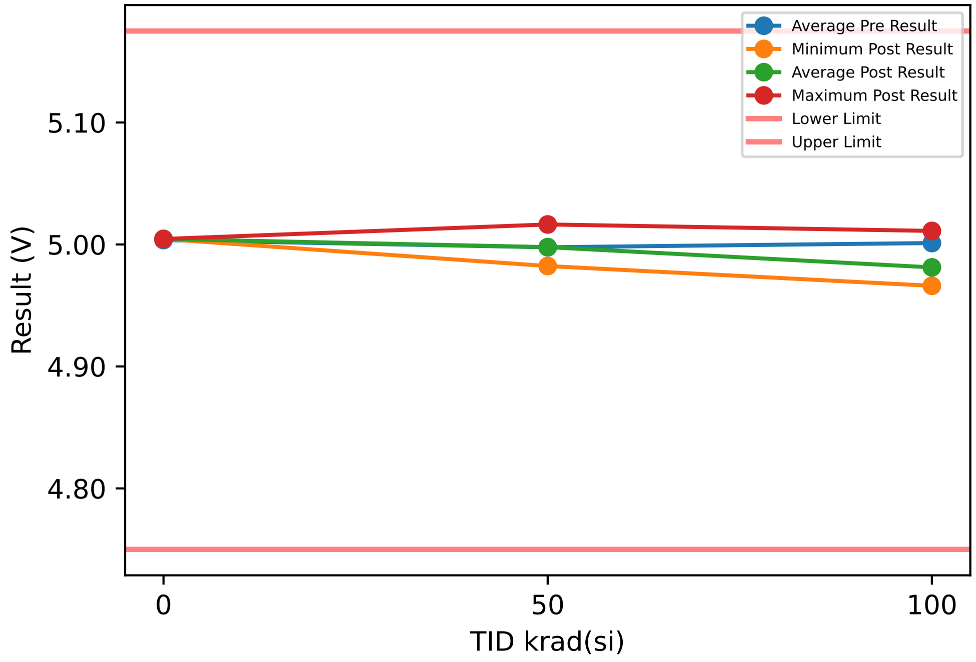
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

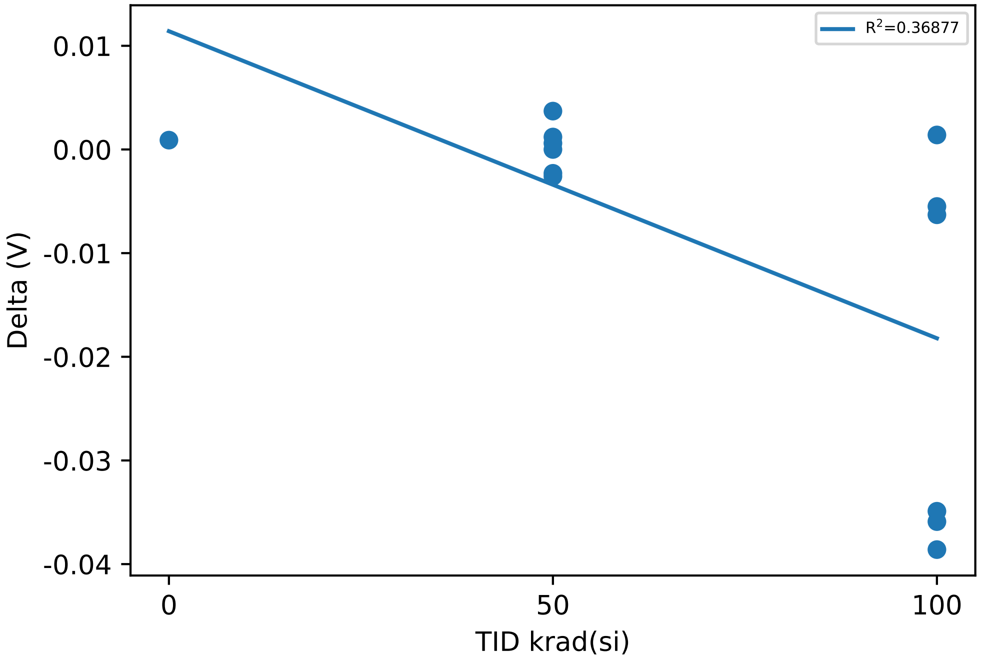
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0589	7.0536	-0.0053
60	50	Biased	7.0222	7.0139	-0.0083
61	50	Biased	7.0399	7.042	0.0021
63	100	Biased	7.0425	7.051	0.0085
64	100	Biased	7.0381	7.015	-0.0231
65	100	Biased	7.0669	7.0674	0.0005
66	50	Unbiased	7.0247	7.0221	-0.0026
67	50	Unbiased	7.0204	7.0338	0.0134
68	50	Unbiased	7.0808	7.0859	0.0051
69	100	Unbiased	7.0309	7.0496	0.0187
70	100	Unbiased	6.9715	6.9963	0.0248
71	100	Unbiased	7.0537	7.0258	-0.0279
72	0	Control	7.0635	7.0628	-0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0635	7.0635	7.0635		7.0628	7.0628	7.0628		-0.0007	-0.0007	-0.0007	
50	7.0204	7.0412	7.0808	0.024286	7.0139	7.0419	7.0859	0.025747	-0.0083	0.00073333	0.0134	0.0078803
100	6.9715	7.0339	7.0669	0.033092	6.9963	7.0342	7.0674	0.026447	-0.0279	0.00025	0.0248	0.021674

Device Test: 61.16 V_BP5L IIM 1MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

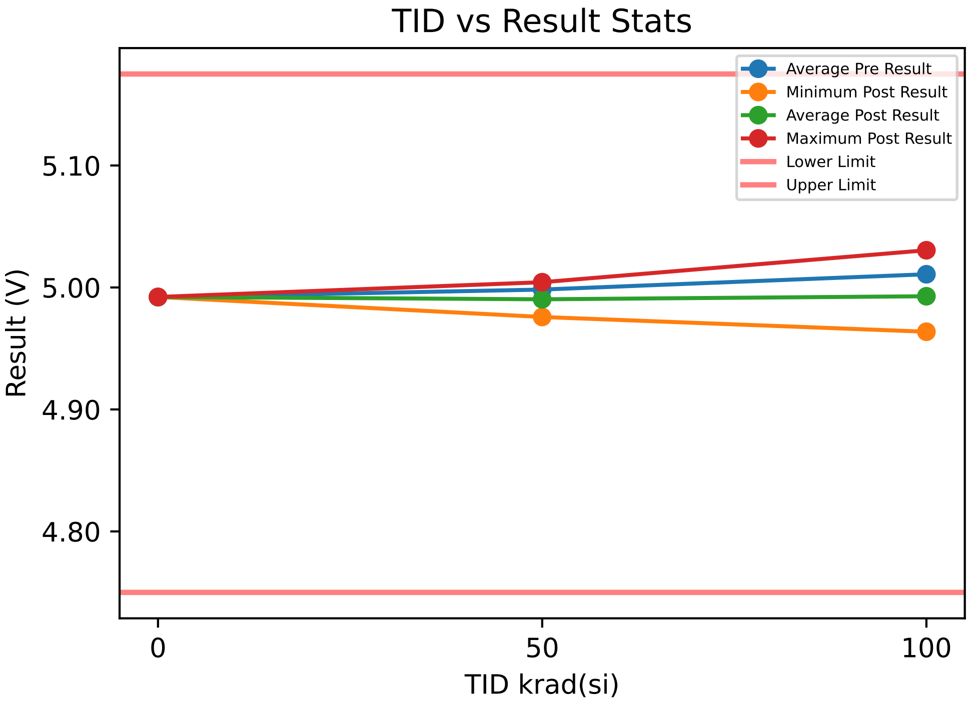
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

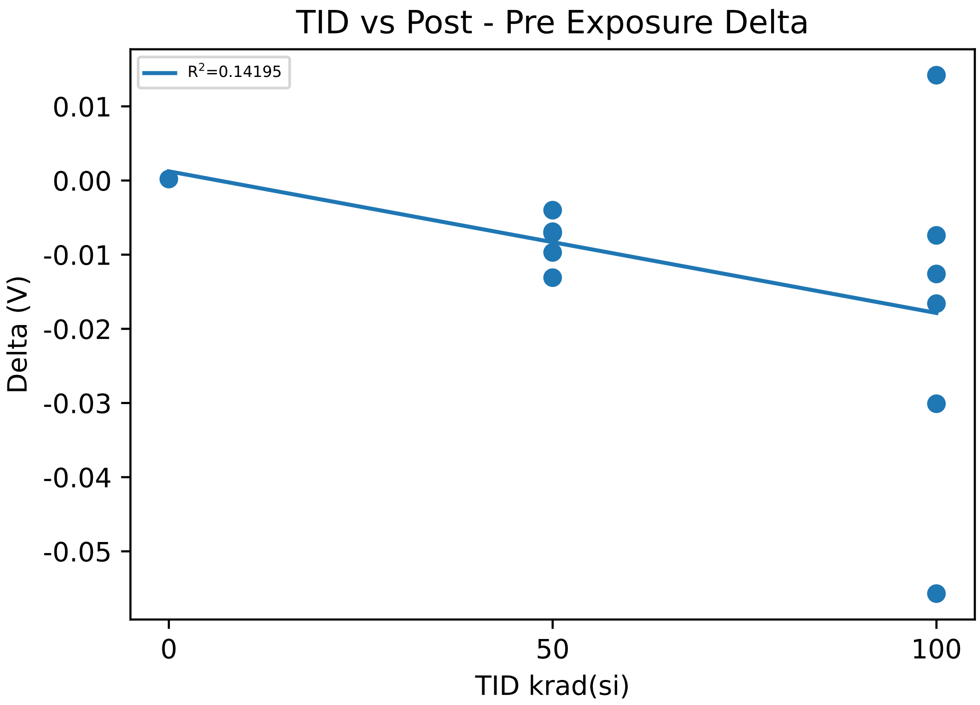
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0028	5.0028	0
60	50	Biased	4.9829	4.9866	0.0037
61	50	Biased	5.0079	5.0091	0.0012
63	100	Biased	5.0027	4.9668	-0.0359
64	100	Biased	4.9897	4.9834	-0.0063
65	100	Biased	5.001	4.9661	-0.0349
66	50	Unbiased	4.9849	4.9823	-0.0026
67	50	Unbiased	4.989	4.9896	0.0006
68	50	Unbiased	5.0187	5.0164	-0.0023
69	100	Unbiased	5.0166	5.0111	-0.0055
70	100	Unbiased	4.9923	4.9937	0.0014
71	100	Unbiased	5.0047	4.9661	-0.0386
72	0	Control	5.0036	5.0045	0.0009

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0036	5.0036	5.0036		5.0045	5.0045	5.0045		0.0009	0.0009	0.0009	
50	4.9829	4.9977	5.0187	0.01435	4.9823	4.9978	5.0164	0.01365	-0.0026	0.0001	0.0037	0.0023444
100	4.9897	5.0012	5.0166	0.0096245	4.9661	4.9812	5.0111	0.018539	-0.0386	-0.019967	0.0014	0.018312

Device Test: 61.17 V_BP5H IIM 1MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

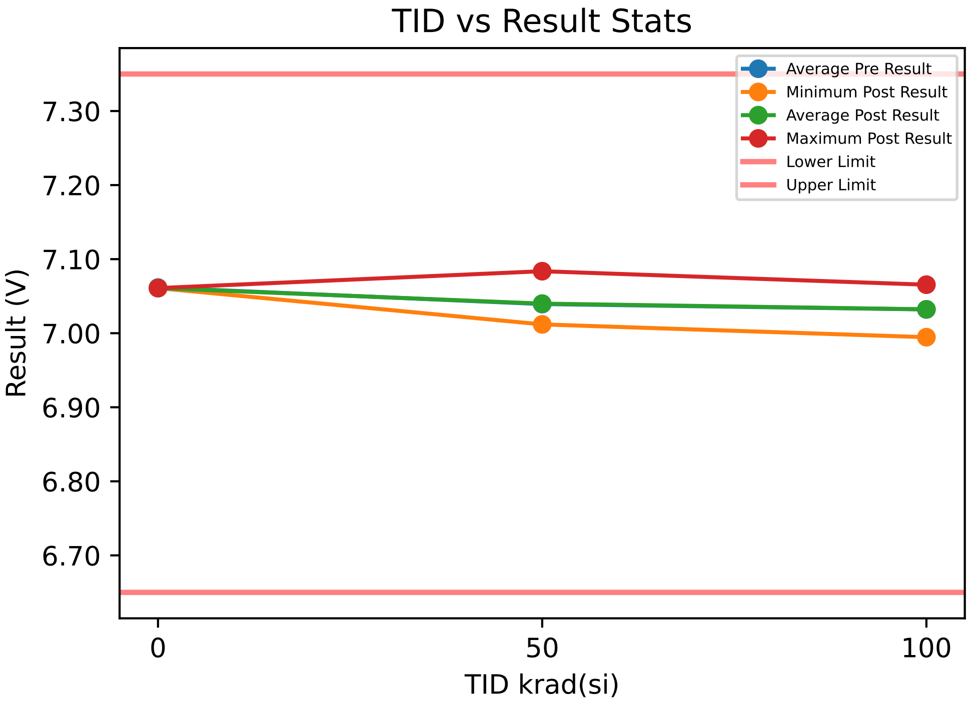
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

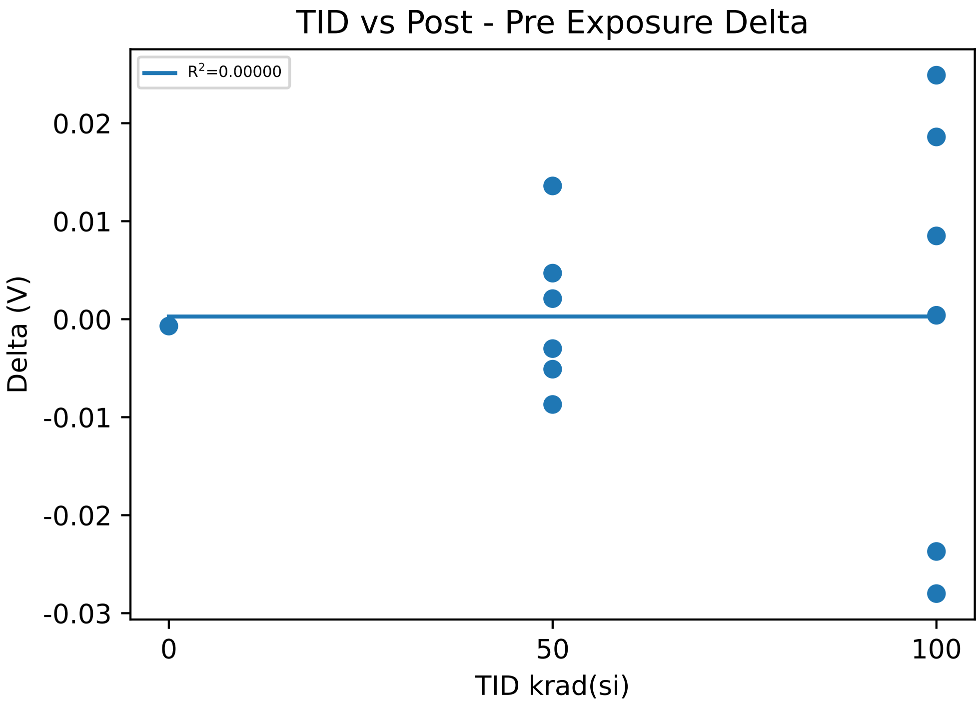
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0029	4.996	-0.0069
60	50	Biased	4.9898	4.9828	-0.007
61	50	Biased	5.0027	4.9987	-0.004
63	100	Biased	4.9982	4.9816	-0.0166
64	100	Biased	5.02	4.9899	-0.0301
65	100	Biased	5.0205	5.0131	-0.0074
66	50	Unbiased	4.9855	4.9758	-0.0097
67	50	Unbiased	4.9913	4.9842	-0.0071
68	50	Unbiased	5.0174	5.0043	-0.0131
69	100	Unbiased	5.0194	4.9637	-0.0557
70	100	Unbiased	4.9905	4.9779	-0.0126
71	100	Unbiased	5.0163	5.0305	0.0142
72	0	Control	4.992	4.9922	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.992	4.992	4.992		4.9922	4.9922	4.9922		0.0002	0.0002	0.0002	
50	4.9855	4.9983	5.0174	0.011751	4.9758	4.9903	5.0043	0.01098	-0.0131	-0.0079667	-0.004	0.0030956
100	4.9905	5.0108	5.0205	0.013067	4.9637	4.9928	5.0305	0.024642	-0.0557	-0.018033	0.0142	0.023444

Device Test: 61.18 V_BP7L IIM 2MHz VIN_12V





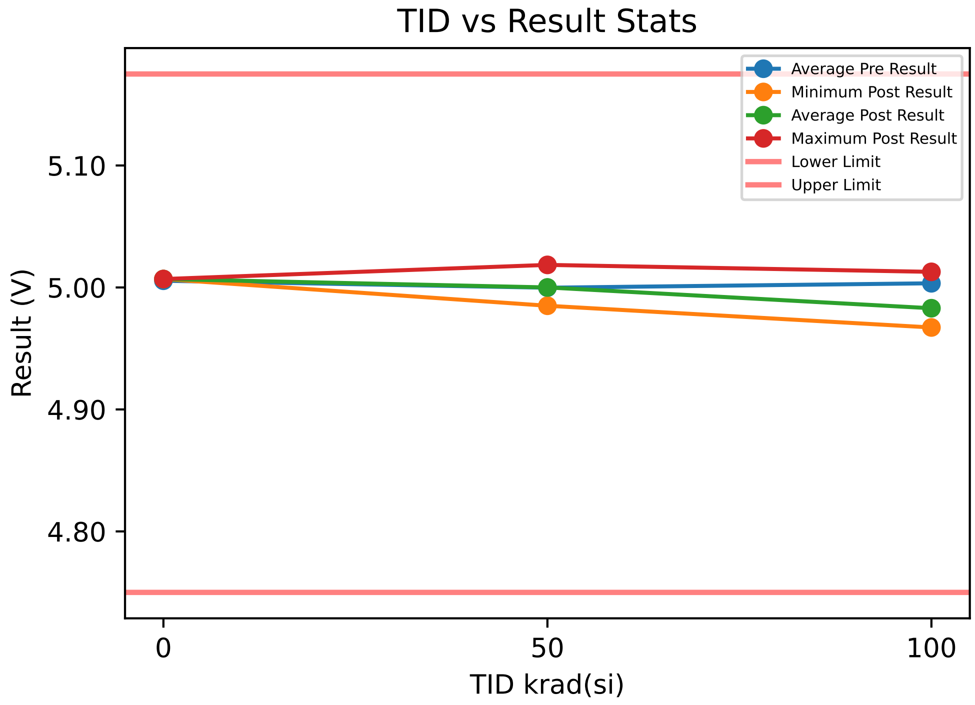
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

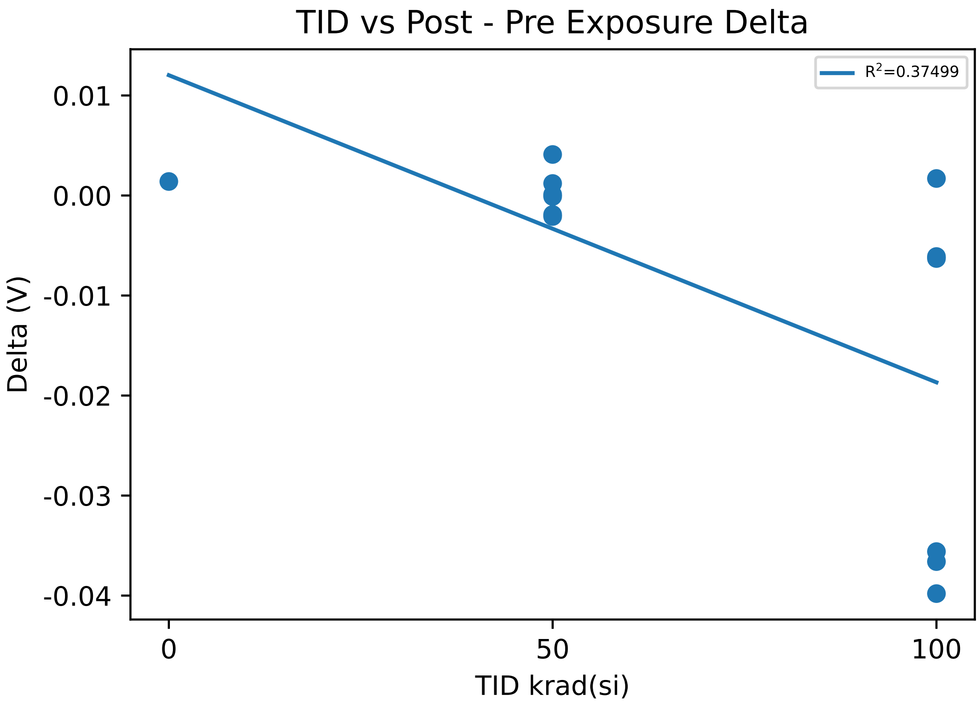
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.057	7.0519	-0.0051
60	50	Biased	7.0206	7.0119	-0.0087
61	50	Biased	7.0381	7.0402	0.0021
63	100	Biased	7.0407	7.0492	0.0085
64	100	Biased	7.0364	7.0127	-0.0237
65	100	Biased	7.0651	7.0655	0.0004
66	50	Unbiased	7.023	7.02	-0.003
67	50	Unbiased	7.0184	7.032	0.0136
68	50	Unbiased	7.079	7.0837	0.0047
69	100	Unbiased	7.0291	7.0477	0.0186
70	100	Unbiased	6.9697	6.9946	0.0249
71	100	Unbiased	7.0517	7.0237	-0.028
72	0	Control	7.0616	7.0609	-0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0616	7.0616	7.0616		7.0609	7.0609	7.0609		-0.0007	-0.0007	-0.0007	
50	7.0184	7.0393	7.079	0.024261	7.0119	7.04	7.0837	0.02571	-0.0087	0.0006	0.0136	0.008
100	6.9697	7.0321	7.0651	0.033071	6.9946	7.0322	7.0655	0.026474	-0.028	0.00011667	0.0249	0.021836

Device Test: 61.19 V_BP5L IIM 2MHz VIN_12V





Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

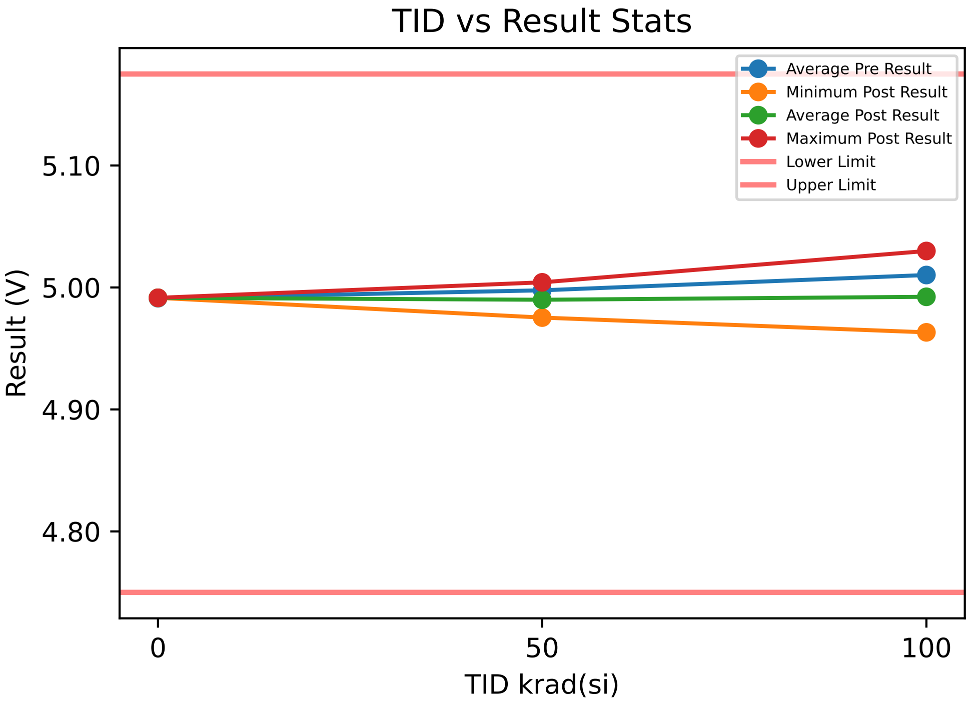
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0051	5.005	-0.0001
60	50	Biased	4.9846	4.9887	0.0041
61	50	Biased	5.0101	5.0113	0.0012
63	100	Biased	5.0049	4.9683	-0.0366
64	100	Biased	4.9914	4.9853	-0.0061
65	100	Biased	5.0037	4.9681	-0.0356
66	50	Unbiased	4.9869	4.985	-0.0019
67	50	Unbiased	4.9915	4.9916	0.0001
68	50	Unbiased	5.0206	5.0185	-0.0021
69	100	Unbiased	5.0191	5.0128	-0.0063
70	100	Unbiased	4.9944	4.9961	0.0017
71	100	Unbiased	5.007	4.9672	-0.0398
72	0	Control	5.0055	5.0069	0.0014

Test Statistics (V)

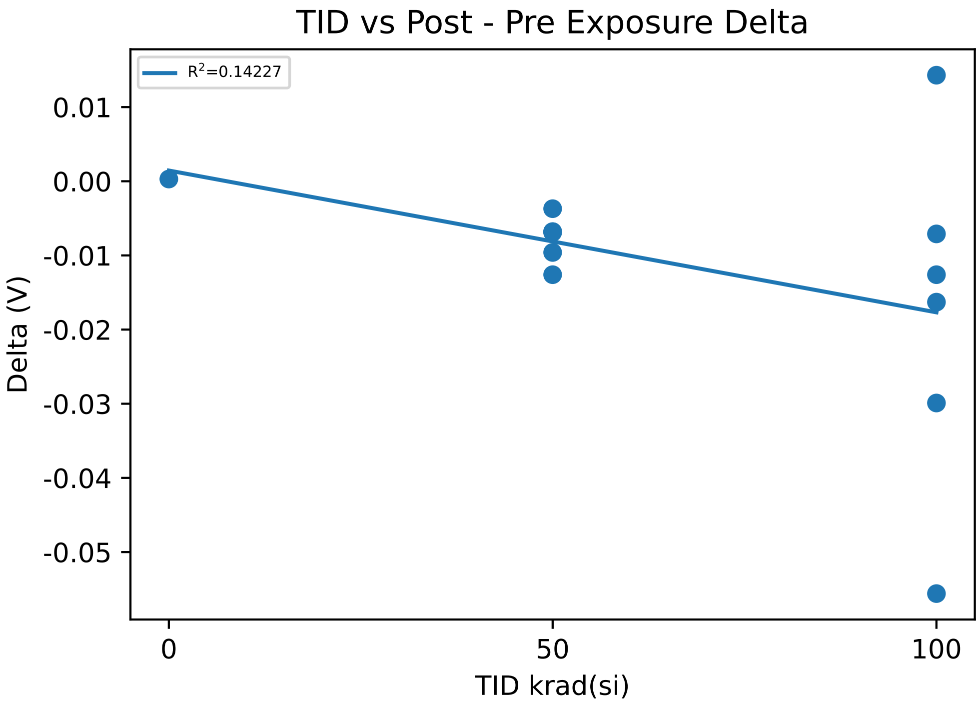
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0055	5.0055	5.0055		5.0069	5.0069	5.0069		0.0014	0.0014	0.0014	
50	4.9846	4.9998	5.0206	0.014375	4.985	5	5.0185	0.013551	-0.0021	0.00021667	0.0041	0.0022807
100	4.9914	5.0034	5.0191	0.009867	4.9672	4.983	5.0128	0.018723	-0.0398	-0.02045	0.0017	0.01877

Device Test: 61.2 V_BP5H PWM 500kHz VIN_12V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



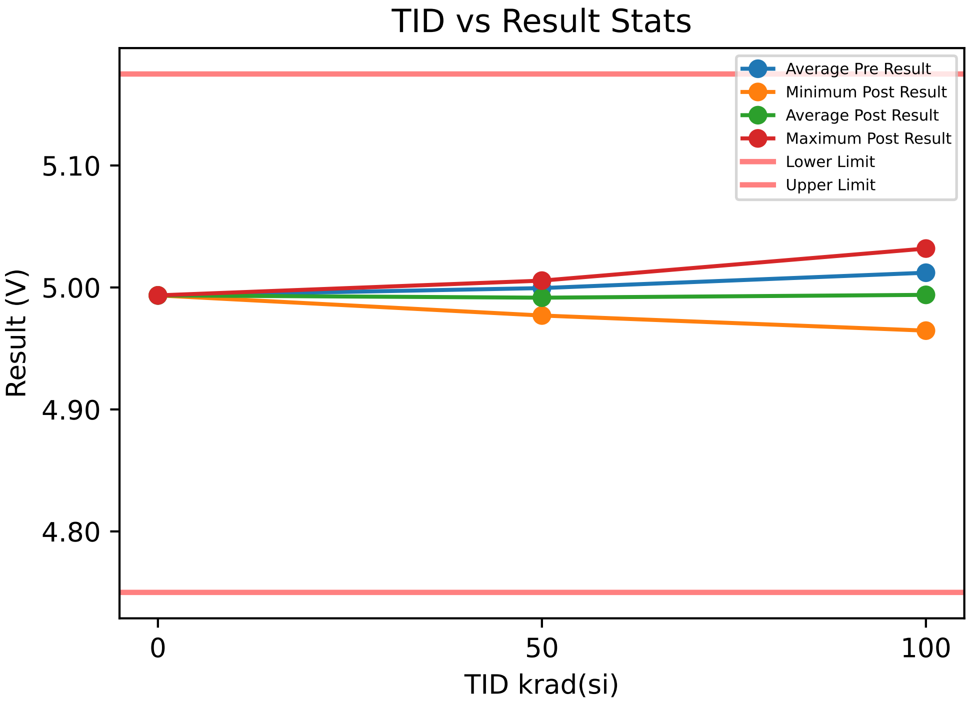
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

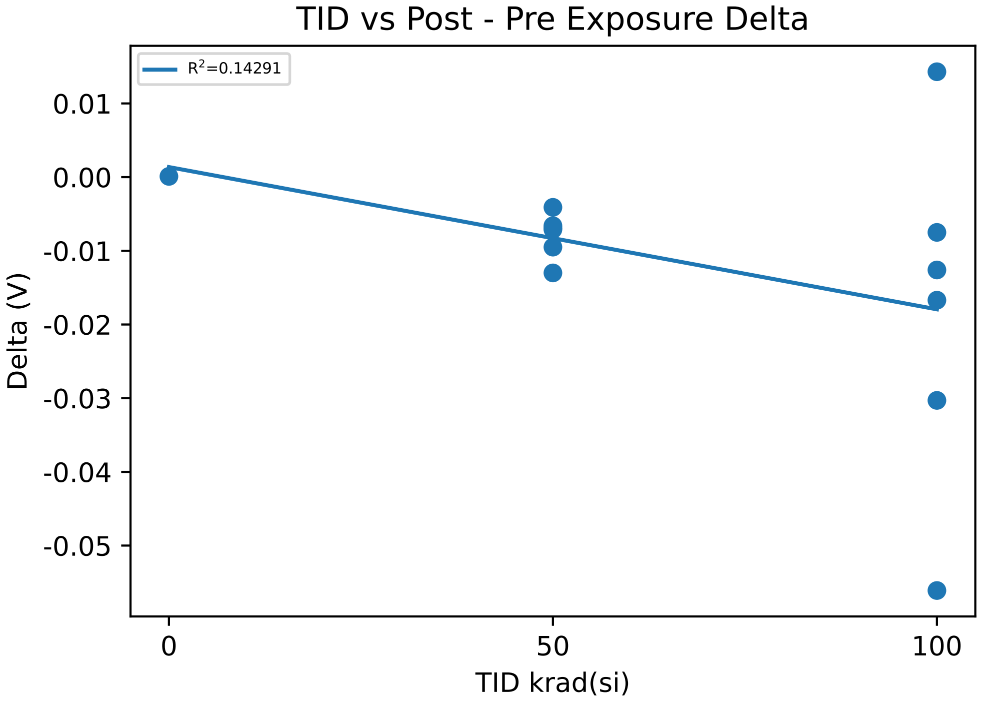
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0023	4.9955	-0.0068
60	50	Biased	4.9892	4.9824	-0.0068
61	50	Biased	5.0021	4.9984	-0.0037
63	100	Biased	4.9975	4.9812	-0.0163
64	100	Biased	5.0196	4.9897	-0.0299
65	100	Biased	5.0198	5.0127	-0.0071
66	50	Unbiased	4.9849	4.9753	-0.0096
67	50	Unbiased	4.9906	4.9837	-0.0069
68	50	Unbiased	5.0168	5.0042	-0.0126
69	100	Unbiased	5.0188	4.9632	-0.0556
70	100	Unbiased	4.9899	4.9773	-0.0126
71	100	Unbiased	5.0156	5.0299	0.0143
72	0	Control	4.9912	4.9915	0.0003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9912	4.9912	4.9912		4.9915	4.9915	4.9915		0.0003	0.0003	0.0003	
50	4.9849	4.9977	5.0168	0.011763	4.9753	4.9899	5.0042	0.011099	-0.0126	-0.0077333	-0.0037	0.003029
100	4.9899	5.0102	5.0198	0.013092	4.9632	4.9923	5.0299	0.024624	-0.0556	-0.017867	0.0143	0.02345

Device Test: 61.20 V_BP5H IIM 2MHz VIN_12V





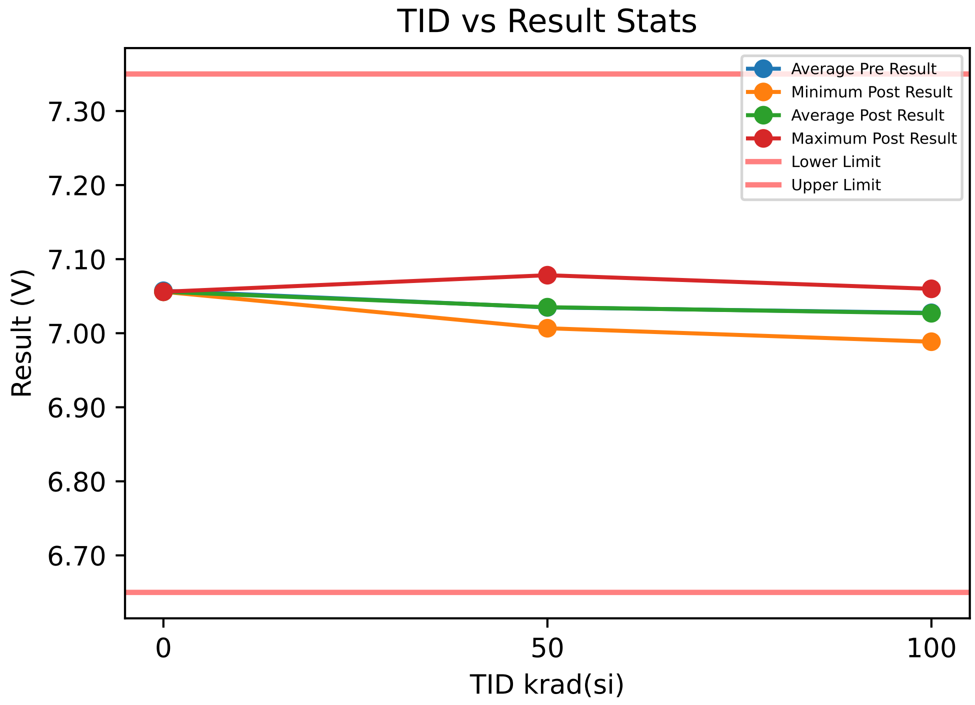
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

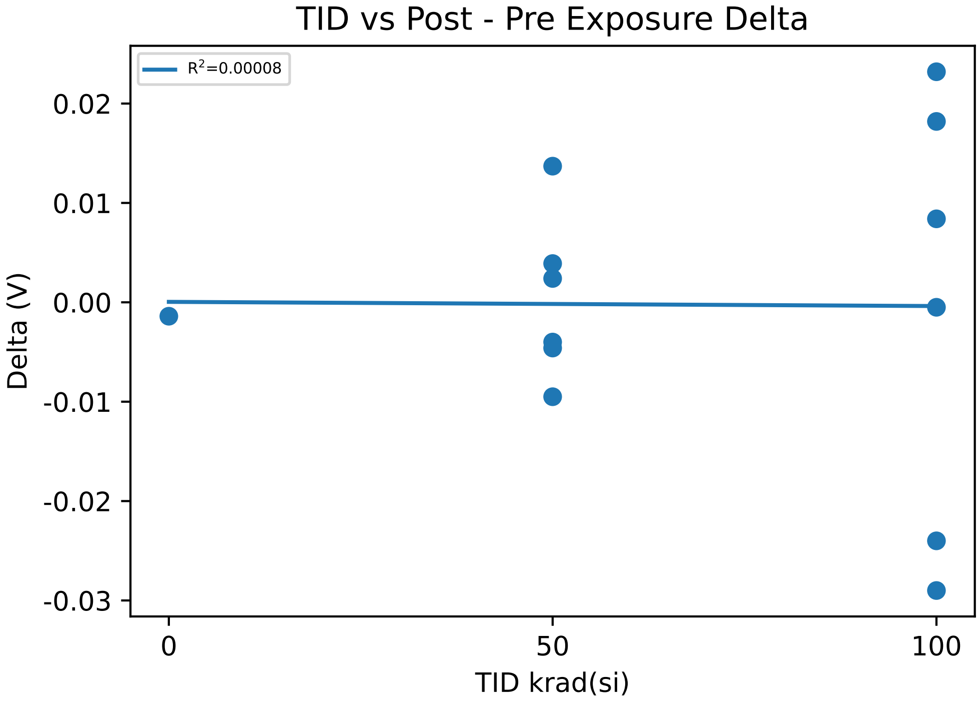
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0041	4.9975	-0.0066
60	50	Biased	4.991	4.9841	-0.0069
61	50	Biased	5.004	4.9999	-0.0041
63	100	Biased	4.9995	4.9828	-0.0167
64	100	Biased	5.0212	4.9909	-0.0303
65	100	Biased	5.0218	5.0143	-0.0075
66	50	Unbiased	4.9865	4.977	-0.0095
67	50	Unbiased	4.9927	4.9856	-0.0071
68	50	Unbiased	5.0186	5.0056	-0.013
69	100	Unbiased	5.0207	4.9646	-0.0561
70	100	Unbiased	4.9917	4.9791	-0.0126
71	100	Unbiased	5.0176	5.0319	0.0143
72	0	Control	4.9934	4.9935	0.0001

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9934	4.9934	4.9934		4.9935	4.9935	4.9935		0.0001	0.0001	0.0001	
50	4.9865	4.9995	5.0186	0.011779	4.977	4.9916	5.0056	0.011001	-0.013	-0.0078667	-0.0041	0.0030441
100	4.9917	5.0121	5.0218	0.013085	4.9646	4.9939	5.0319	0.024779	-0.0561	-0.01815	0.0143	0.02361

Device Test: 61.21 V_BP7L IIM 5MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

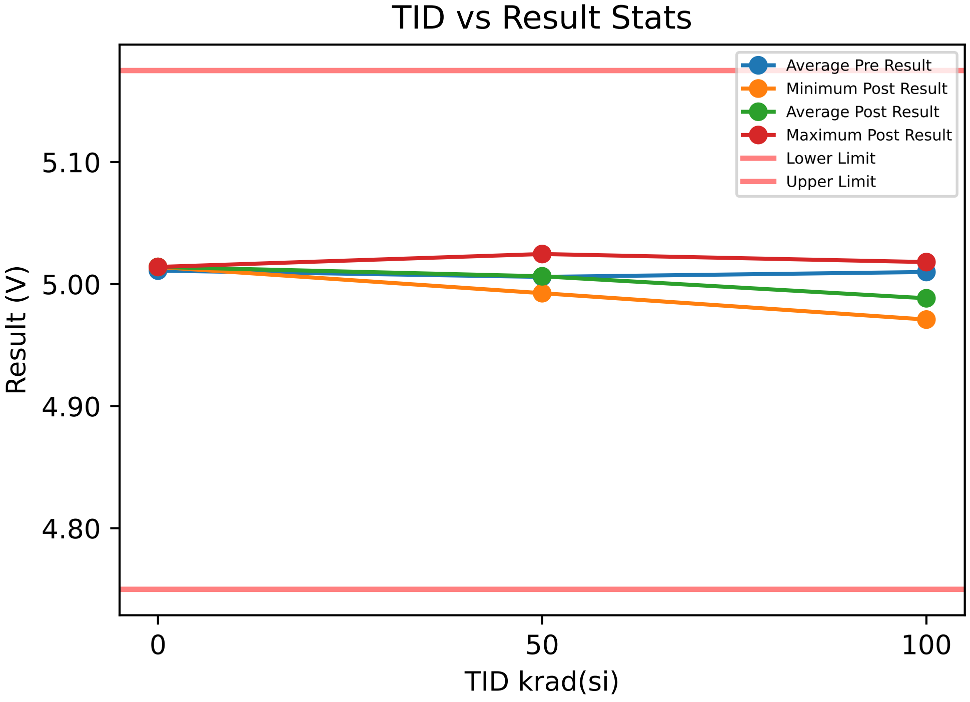
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0522	7.0476	-0.0046
60	50	Biased	7.0162	7.0067	-0.0095
61	50	Biased	7.0335	7.0359	0.0024
63	100	Biased	7.0362	7.0446	0.0084
64	100	Biased	7.0319	7.0079	-0.024
65	100	Biased	7.0604	7.0599	-0.0005
66	50	Unbiased	7.0187	7.0147	-0.004
67	50	Unbiased	7.0138	7.0275	0.0137
68	50	Unbiased	7.0744	7.0783	0.0039
69	100	Unbiased	7.0245	7.0427	0.0182
70	100	Unbiased	6.9653	6.9885	0.0232
71	100	Unbiased	7.0468	7.0178	-0.029
72	0	Control	7.0573	7.0559	-0.0014

Test Statistics (V)

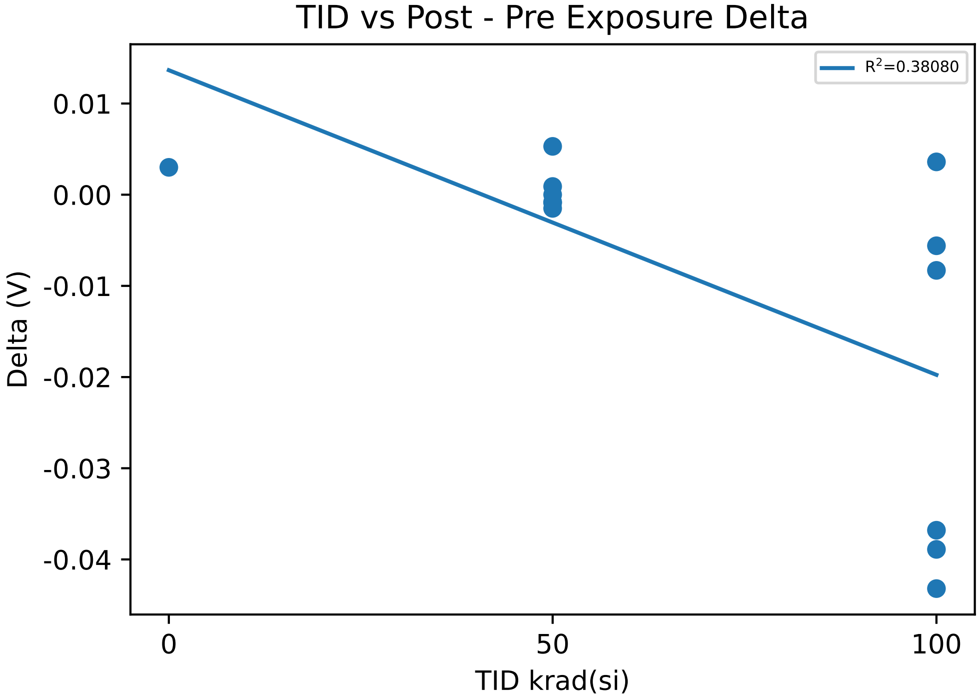
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0573	7.0573	7.0573		7.0559	7.0559	7.0559		-0.0014	-0.0014	-0.0014	
50	7.0138	7.0348	7.0744	0.024161	7.0067	7.0351	7.0783	0.025705	-0.0095	0.00031667	0.0137	0.0081911
100	6.9653	7.0275	7.0604	0.032948	6.9885	7.0269	7.0599	0.026722	-0.029	-0.00061667	0.0232	0.021703

Device Test: 61.22 V_BP5L IIM 5MHz VIN_12V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



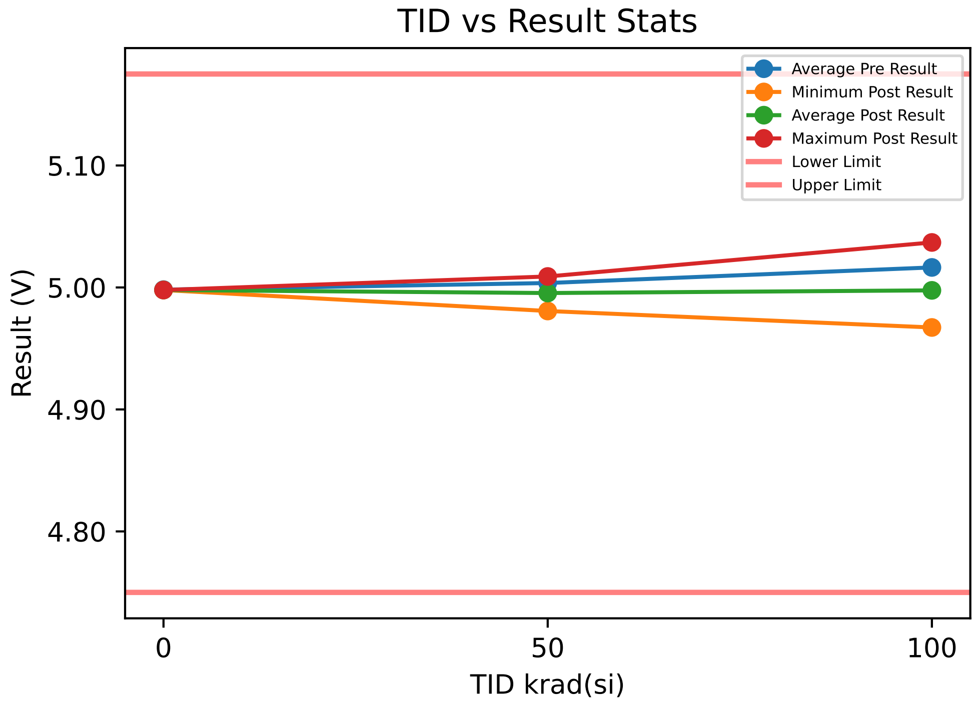
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

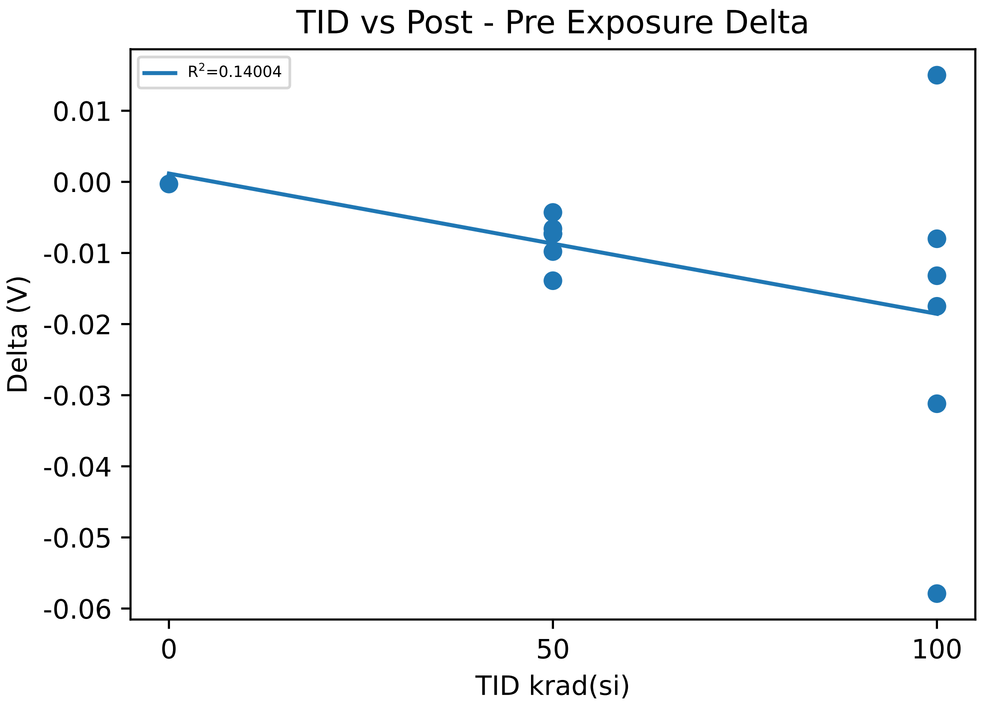
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0123	5.0115	-0.0008
60	50	Biased	4.9896	4.9949	0.0053
61	50	Biased	5.0167	5.0176	0.0009
63	100	Biased	5.0116	4.9727	-0.0389
64	100	Biased	4.9962	4.9906	-0.0056
65	100	Biased	5.0115	4.9747	-0.0368
66	50	Unbiased	4.9926	4.9926	0
67	50	Unbiased	4.9989	4.9974	-0.0015
68	50	Unbiased	5.0256	5.0247	-0.0009
69	100	Unbiased	5.0264	5.0181	-0.0083
70	100	Unbiased	4.9999	5.0035	0.0036
71	100	Unbiased	5.0142	4.971	-0.0432
72	0	Control	5.0111	5.0141	0.003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0111	5.0111	5.0111		5.0141	5.0141	5.0141		0.003	0.003	0.003	
50	4.9896	5.0059	5.0256	0.014403	4.9926	5.0065	5.0247	0.013342	-0.0015	0.0005	0.0053	0.002494
100	4.9962	5.01	5.0264	0.010806	4.971	4.9884	5.0181	0.019245	-0.0432	-0.021533	0.0036	0.020321

Device Test: 61.23 V_BP5H IIM 5MHz VIN_12V





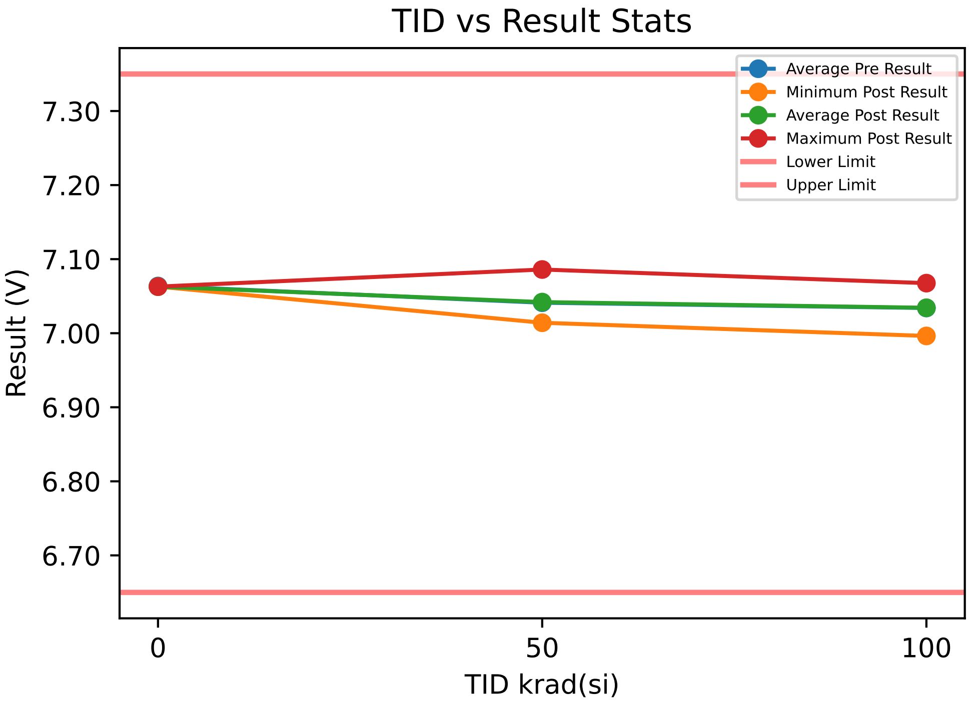
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

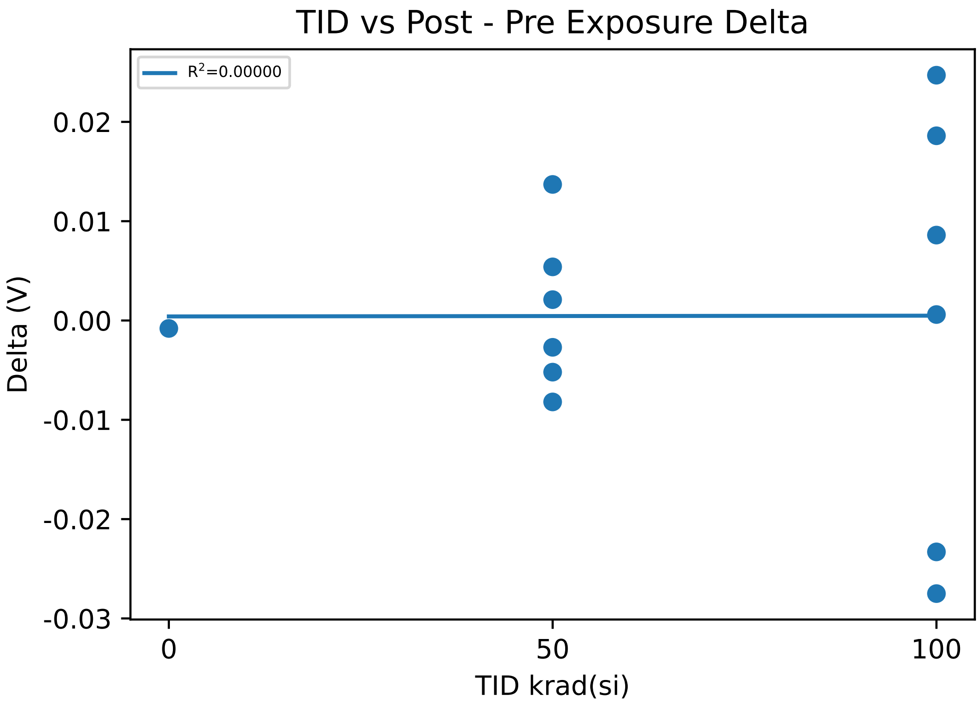
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.008	5.0014	-0.0066
60	50	Biased	4.9952	4.9879	-0.0073
61	50	Biased	5.0082	5.0039	-0.0043
63	100	Biased	5.0039	4.9864	-0.0175
64	100	Biased	5.0254	4.9942	-0.0312
65	100	Biased	5.0261	5.0181	-0.008
66	50	Unbiased	4.9905	4.9807	-0.0098
67	50	Unbiased	4.997	4.9897	-0.0073
68	50	Unbiased	5.0229	5.009	-0.0139
69	100	Unbiased	5.0251	4.9672	-0.0579
70	100	Unbiased	4.9961	4.9829	-0.0132
71	100	Unbiased	5.0219	5.0369	0.015
72	0	Control	4.9982	4.9979	-0.0003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9982	4.9982	4.9982		4.9979	4.9979	4.9979		-0.0003	-0.0003	-0.0003	
50	4.9905	5.0036	5.0229	0.011821	4.9807	4.9954	5.009	0.010936	-0.0139	-0.0082	-0.0043	0.0032997
100	4.9961	5.0164	5.0261	0.013034	4.9672	4.9976	5.0369	0.025464	-0.0579	-0.0188	0.015	0.024391

Device Test: 61.3 V_BP7L PWM 1MHz VIN_12V





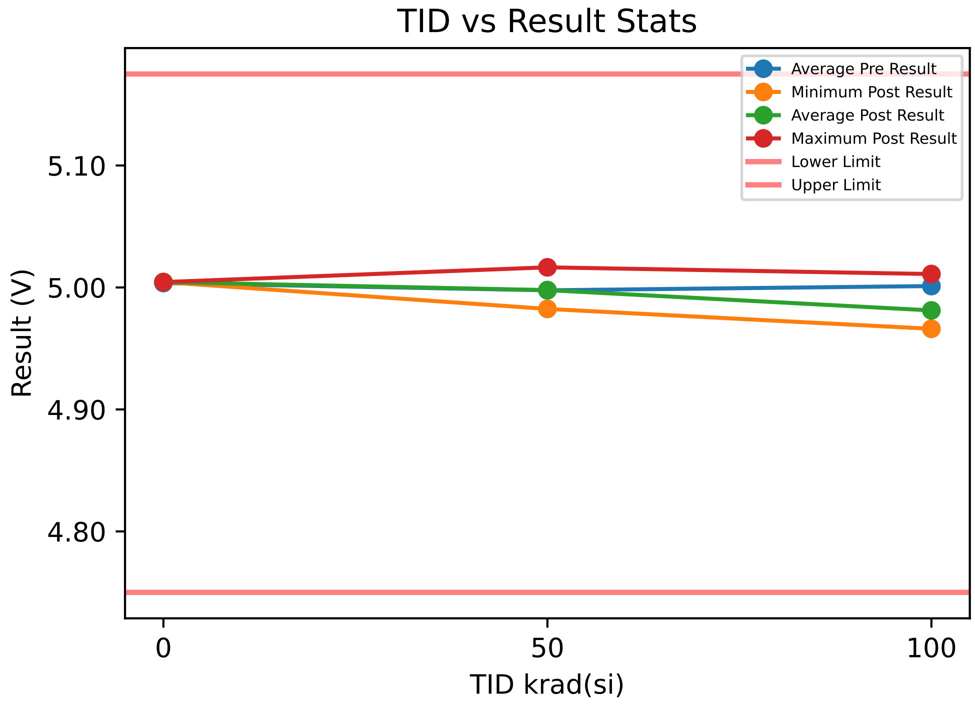
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

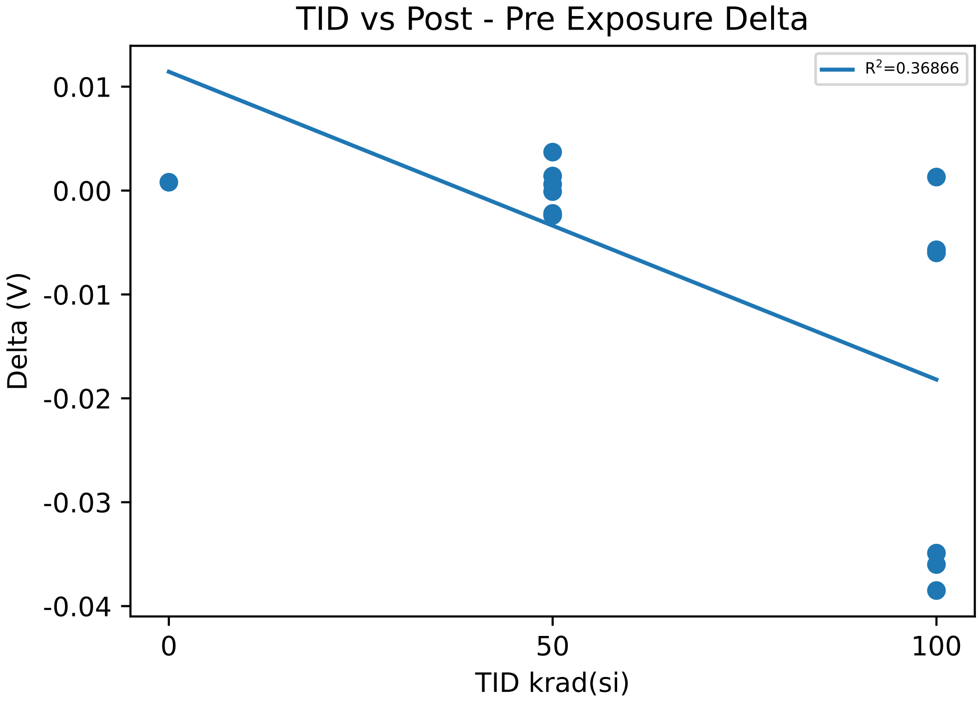
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.059	7.0538	-0.0052
60	50	Biased	7.0223	7.0141	-0.0082
61	50	Biased	7.0398	7.0419	0.0021
63	100	Biased	7.0426	7.0512	0.0086
64	100	Biased	7.0383	7.015	-0.0233
65	100	Biased	7.067	7.0676	0.0006
66	50	Unbiased	7.025	7.0223	-0.0027
67	50	Unbiased	7.0203	7.034	0.0137
68	50	Unbiased	7.0806	7.086	0.0054
69	100	Unbiased	7.031	7.0496	0.0186
70	100	Unbiased	6.9716	6.9963	0.0247
71	100	Unbiased	7.0538	7.0263	-0.0275
72	0	Control	7.0637	7.0629	-0.0008

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0637	7.0637	7.0637		7.0629	7.0629	7.0629		-0.0008	-0.0008	-0.0008	
50	7.0203	7.0412	7.0806	0.024198	7.0141	7.042	7.086	0.025713	-0.0082	0.00085	0.0137	0.0079812
100	6.9716	7.034	7.067	0.033095	6.9963	7.0343	7.0676	0.026492	-0.0275	0.00028333	0.0247	0.021583

Device Test: 61.4 V_BP5L PWM 1MHz VIN_12V





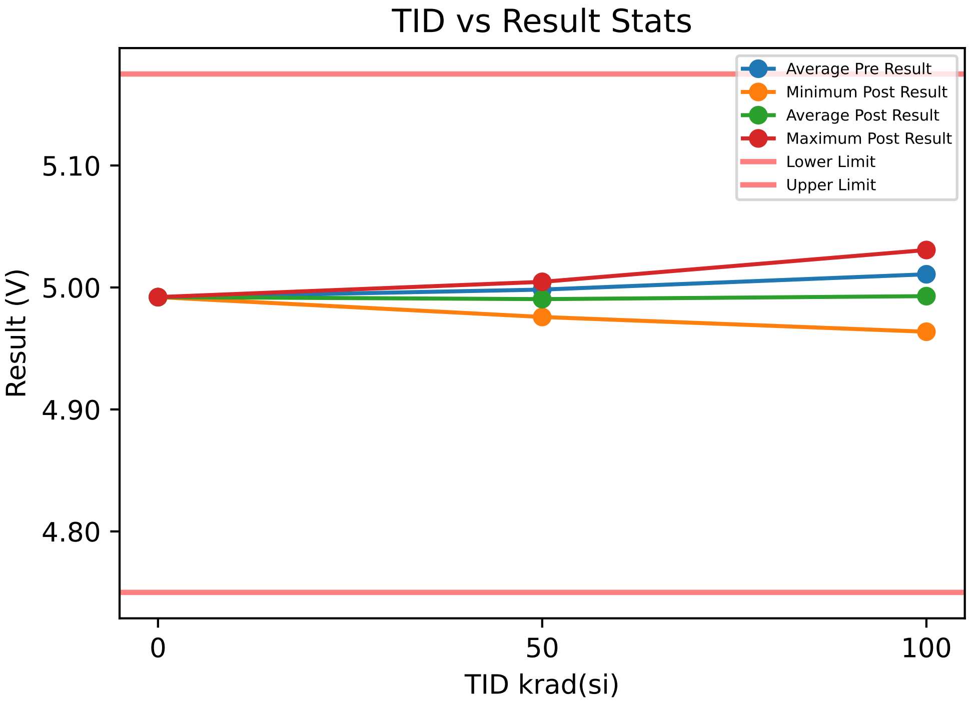
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

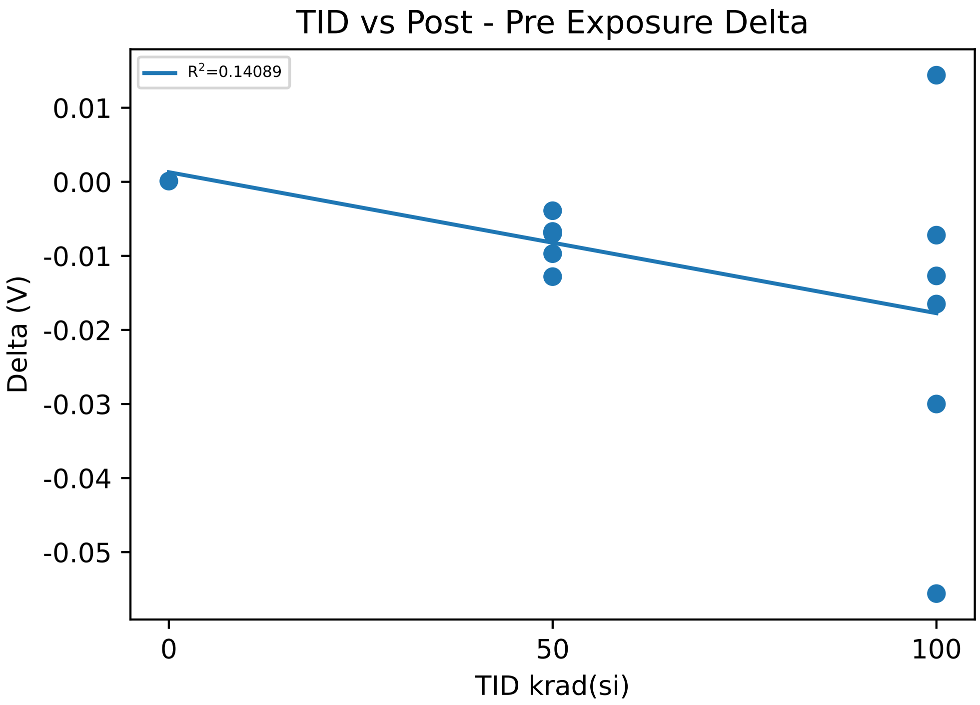
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0028	5.0027	-0.0001
60	50	Biased	4.9829	4.9866	0.0037
61	50	Biased	5.0077	5.0091	0.0014
63	100	Biased	5.0026	4.9666	-0.036
64	100	Biased	4.9896	4.9836	-0.006
65	100	Biased	5.001	4.9661	-0.0349
66	50	Unbiased	4.9848	4.9824	-0.0024
67	50	Unbiased	4.9891	4.9897	0.0006
68	50	Unbiased	5.0187	5.0165	-0.0022
69	100	Unbiased	5.0167	5.011	-0.0057
70	100	Unbiased	4.9924	4.9937	0.0013
71	100	Unbiased	5.0046	4.9661	-0.0385
72	0	Control	5.0036	5.0044	0.0008

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0036	5.0036	5.0036		5.0044	5.0044	5.0044		0.0008	0.0008	0.0008	
50	4.9829	4.9977	5.0187	0.014328	4.9824	4.9978	5.0165	0.013635	-0.0024	0.00016667	0.0037	0.0023001
100	4.9896	5.0011	5.0167	0.0096519	4.9661	4.9812	5.011	0.018543	-0.0385	-0.019967	0.0013	0.0183

Device Test: 61.5 V_BP5H PWM 1MHz VIN_12V





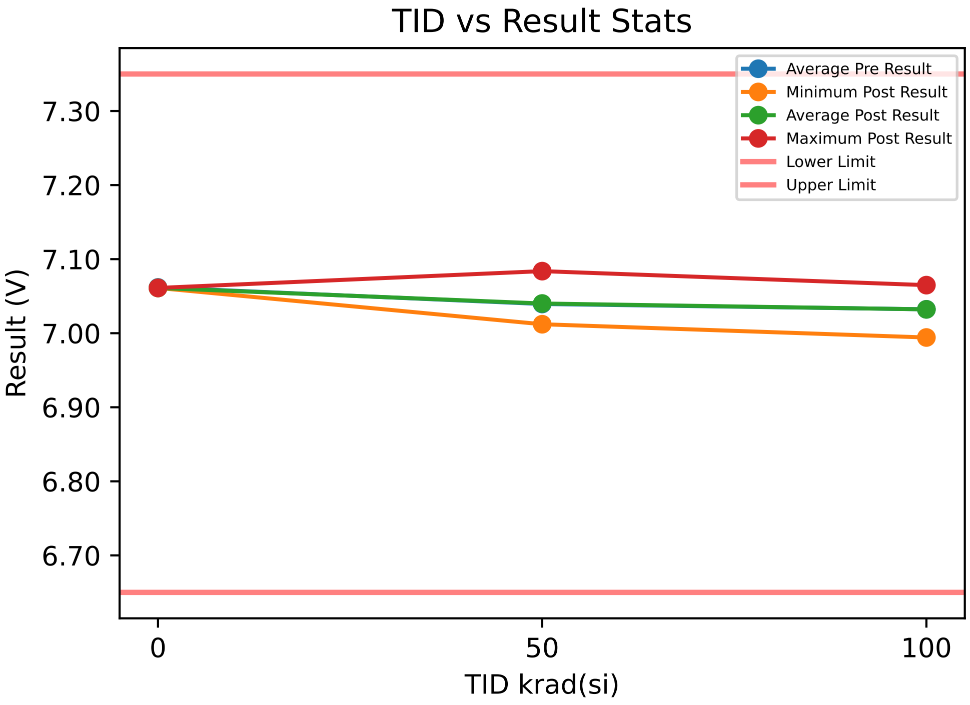
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0029	4.9962	-0.0067
60	50	Biased	4.9898	4.9828	-0.007
61	50	Biased	5.0027	4.9988	-0.0039
63	100	Biased	4.9981	4.9816	-0.0165
64	100	Biased	5.0201	4.9901	-0.03
65	100	Biased	5.0204	5.0132	-0.0072
66	50	Unbiased	4.9855	4.9758	-0.0097
67	50	Unbiased	4.9912	4.9844	-0.0068
68	50	Unbiased	5.0174	5.0046	-0.0128
69	100	Unbiased	5.0193	4.9637	-0.0556
70	100	Unbiased	4.9906	4.9779	-0.0127
71	100	Unbiased	5.0163	5.0307	0.0144
72	0	Control	4.992	4.9921	0.0001

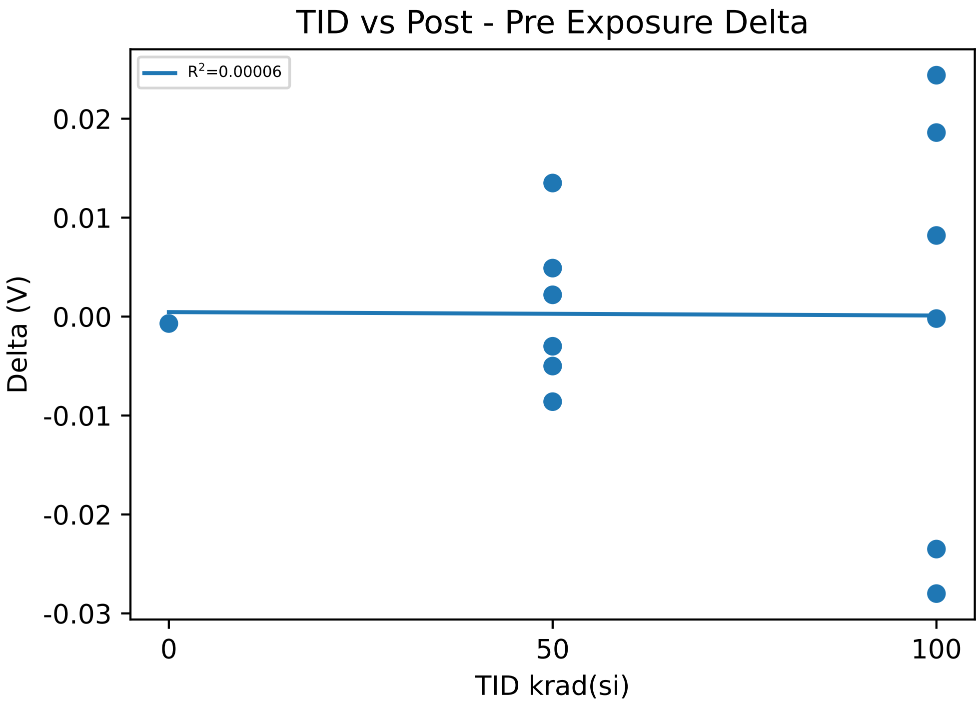
Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.992	4.992	4.992		4.9921	4.9921	4.9921		0.0001	0.0001	0.0001	
50	4.9855	4.9982	5.0174	0.011763	4.9758	4.9904	5.0046	0.01107	-0.0128	-0.0078167	-0.0039	0.0030551
100	4.9906	5.0108	5.0204	0.013042	4.9637	4.9929	5.0307	0.024715	-0.0556	-0.017933	0.0144	0.023471

Device Test: 61.6 V_BP7L PWM 2MHz VIN_12V



TID vs Result Stats



TID vs Post - Pre Exposure Delta

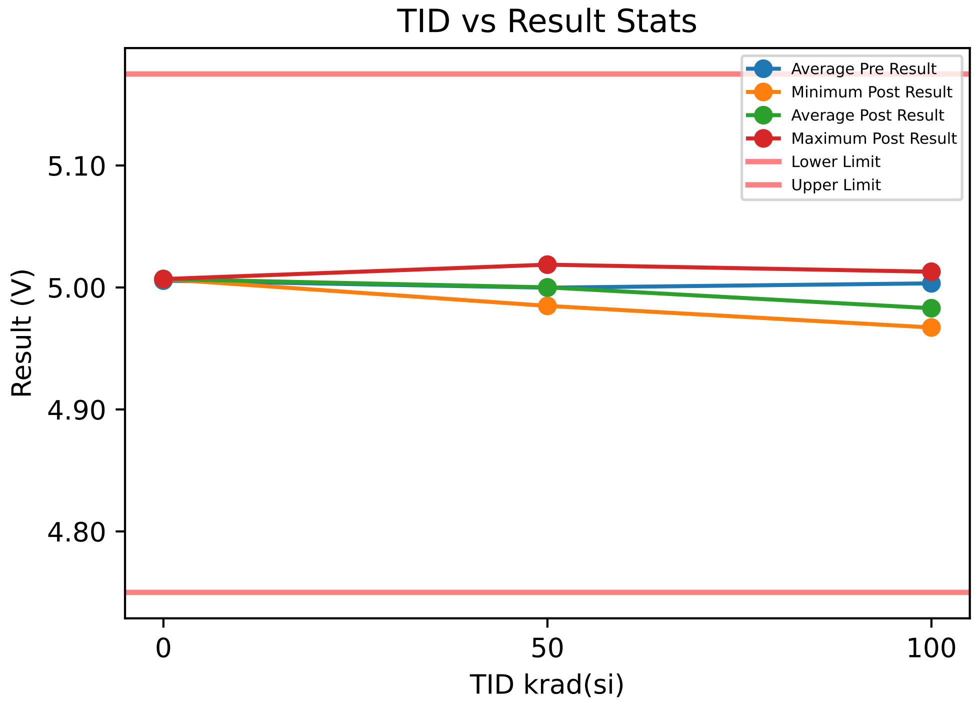
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

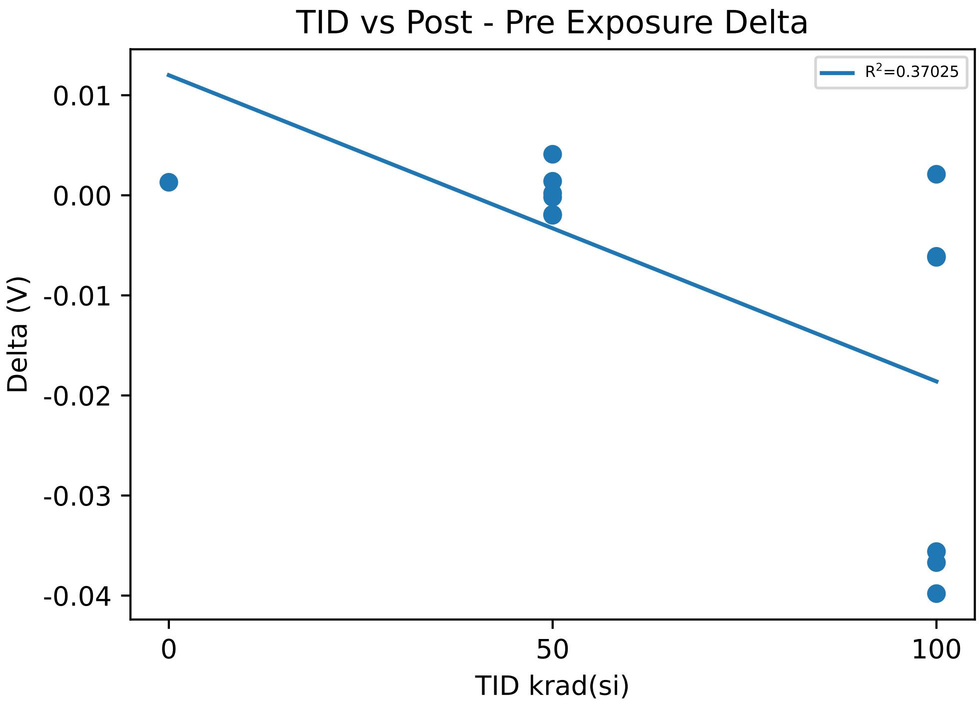
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0571	7.0521	-0.005
60	50	Biased	7.0207	7.0121	-0.0086
61	50	Biased	7.038	7.0402	0.0022
63	100	Biased	7.041	7.0492	0.0082
64	100	Biased	7.0365	7.013	-0.0235
65	100	Biased	7.0651	7.0649	-0.0002
66	50	Unbiased	7.0233	7.0203	-0.003
67	50	Unbiased	7.0186	7.0321	0.0135
68	50	Unbiased	7.0789	7.0838	0.0049
69	100	Unbiased	7.0292	7.0478	0.0186
70	100	Unbiased	6.9698	6.9942	0.0244
71	100	Unbiased	7.052	7.024	-0.028
72	0	Control	7.0618	7.0611	-0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0618	7.0618	7.0618		7.0611	7.0611	7.0611		-0.0007	-0.0007	-0.0007	
50	7.0186	7.0394	7.0789	0.024154	7.0121	7.0401	7.0838	0.025666	-0.0086	0.00066667	0.0135	0.0079548
100	6.9698	7.0323	7.0651	0.033085	6.9942	7.0322	7.0649	0.026388	-0.028	-8.3333e-05	0.0244	0.021656

Device Test: 61.7 V_BP5L PWM 2MHz VIN_12V





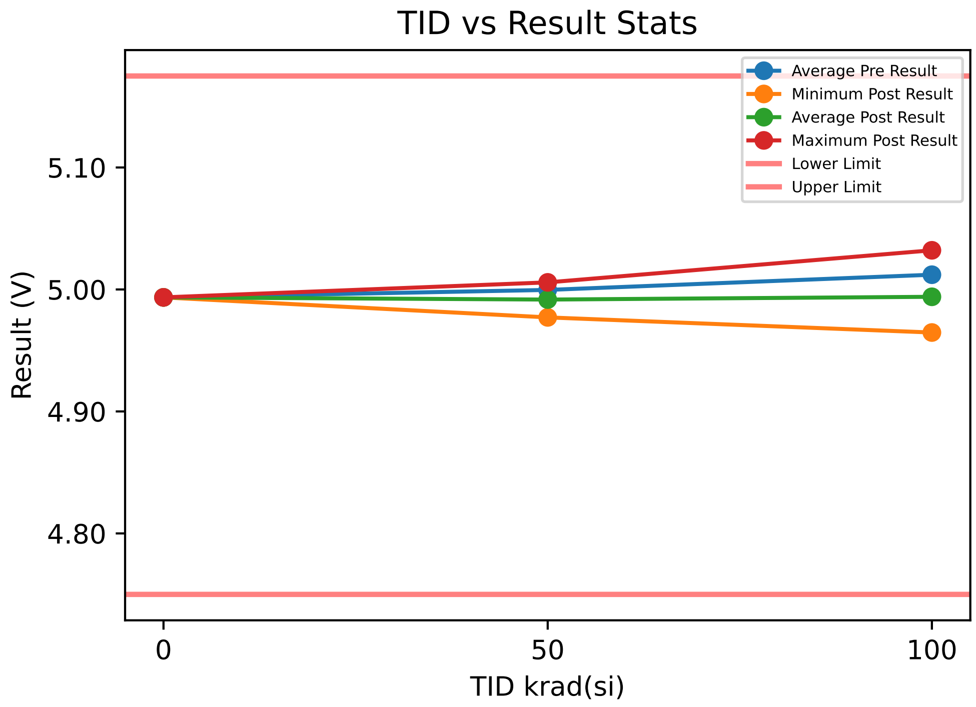
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0052	5.005	-0.0002
60	50	Biased	4.9847	4.9888	0.0041
61	50	Biased	5.01	5.0114	0.0014
63	100	Biased	5.0048	4.9681	-0.0367
64	100	Biased	4.9914	4.9853	-0.0061
65	100	Biased	5.0036	4.968	-0.0356
66	50	Unbiased	4.9869	4.9849	-0.002
67	50	Unbiased	4.9915	4.9917	0.0002
68	50	Unbiased	5.0206	5.0187	-0.0019
69	100	Unbiased	5.0191	5.0129	-0.0062
70	100	Unbiased	4.9943	4.9964	0.0021
71	100	Unbiased	5.007	4.9672	-0.0398
72	0	Control	5.0056	5.0069	0.0013

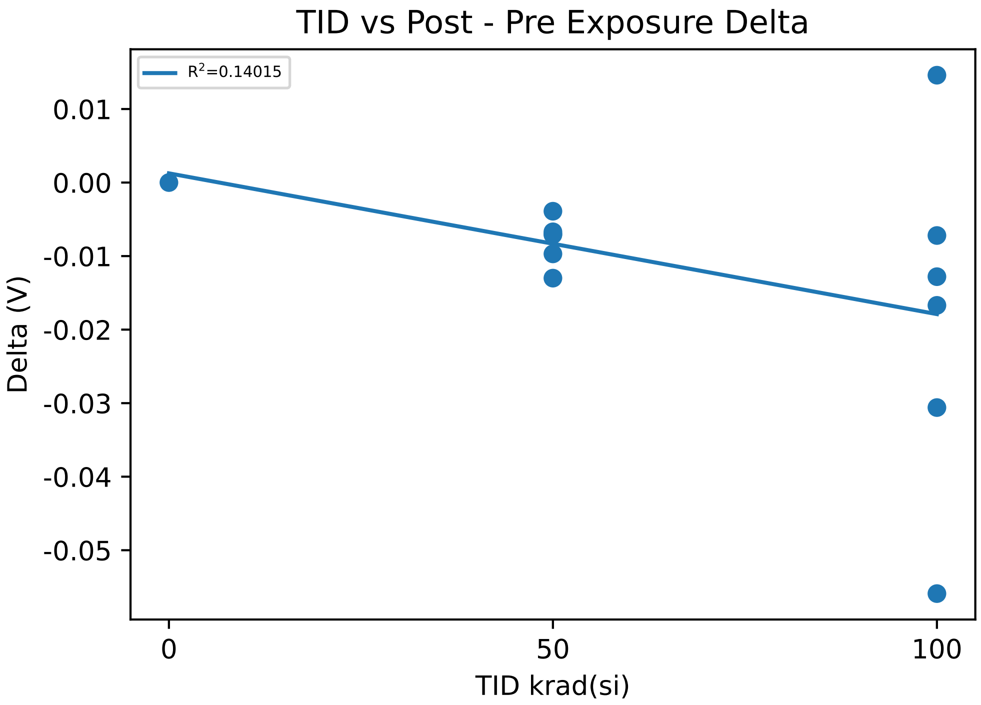
Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0056	5.0056	5.0056		5.0069	5.0069	5.0069		0.0013	0.0013	0.0013	
50	4.9847	4.9998	5.0206	0.014347	4.9849	5.0001	5.0187	0.013616	-0.002	0.00026667	0.0041	0.0022818
100	4.9914	5.0034	5.0191	0.0098818	4.9672	4.983	5.0129	0.018844	-0.0398	-0.020383	0.0021	0.018897

Device Test: 61.8 V_BP5H PWM 2MHz VIN_12V



TID vs Result Stats



TID vs Post - Pre Exposure Delta

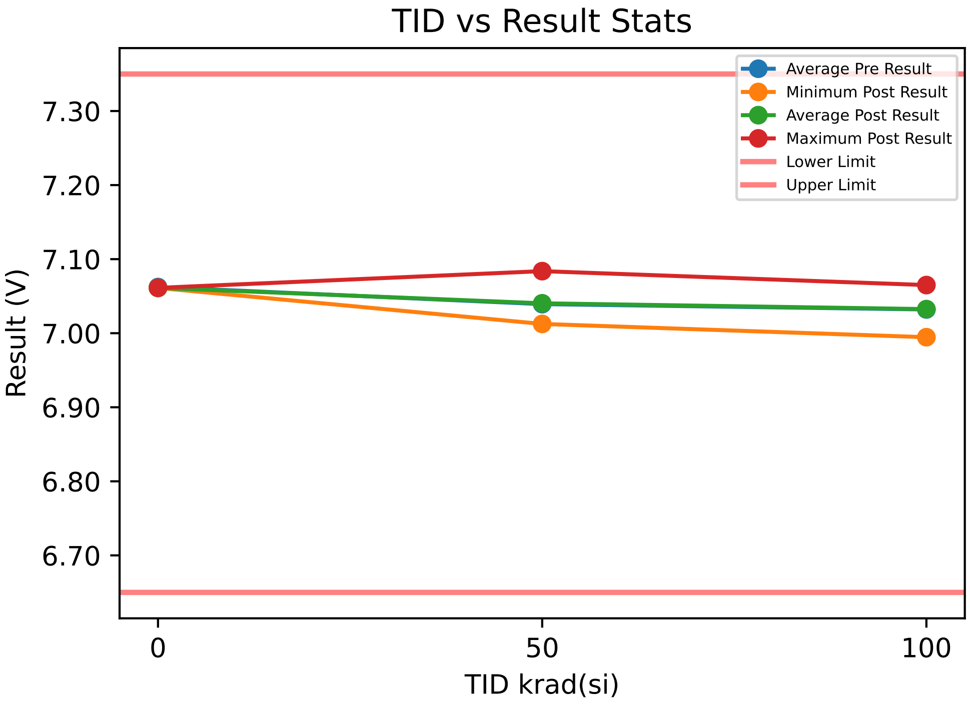
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

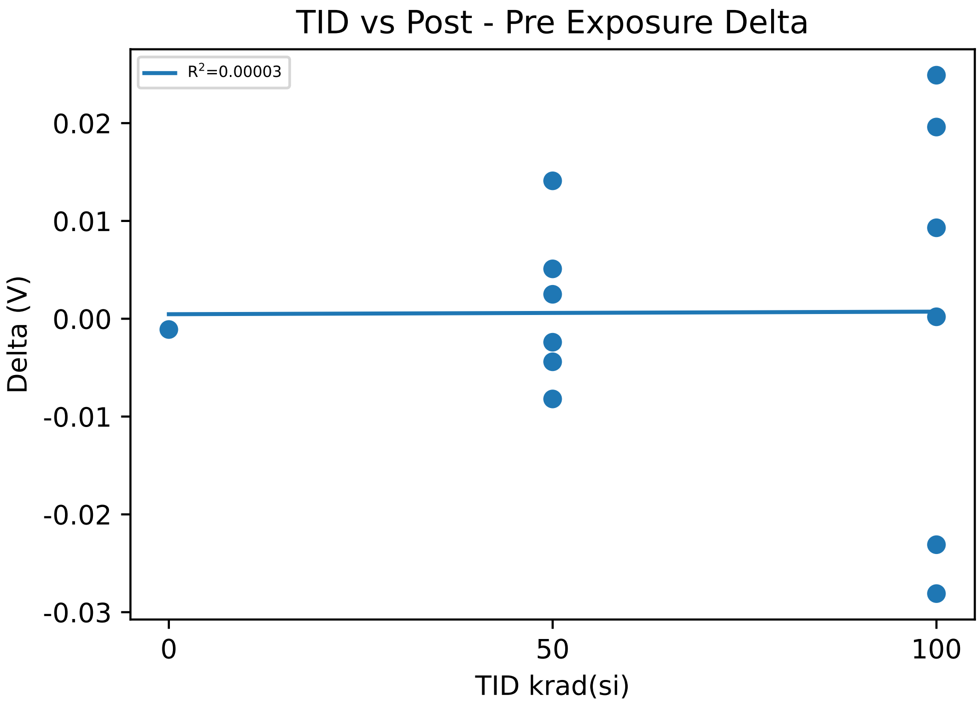
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0042	4.9975	-0.0067
60	50	Biased	4.9911	4.984	-0.0071
61	50	Biased	5.0041	5.0002	-0.0039
63	100	Biased	4.9995	4.9828	-0.0167
64	100	Biased	5.0214	4.9908	-0.0306
65	100	Biased	5.0216	5.0144	-0.0072
66	50	Unbiased	4.9868	4.9771	-0.0097
67	50	Unbiased	4.9927	4.9857	-0.007
68	50	Unbiased	5.0188	5.0058	-0.013
69	100	Unbiased	5.0206	4.9647	-0.0559
70	100	Unbiased	4.9919	4.9791	-0.0128
71	100	Unbiased	5.0175	5.0321	0.0146
72	0	Control	4.9935	4.9935	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9935	4.9935	4.9935		4.9935	4.9935	4.9935		0	0	0	
50	4.9868	4.9996	5.0188	0.011779	4.9771	4.9917	5.0058	0.011074	-0.013	-0.0079	-0.0039	0.0031029
100	4.9919	5.0121	5.0216	0.013	4.9647	4.994	5.0321	0.024835	-0.0559	-0.0181	0.0146	0.023678

Device Test: 61.9 V_BP7L PWM 5MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

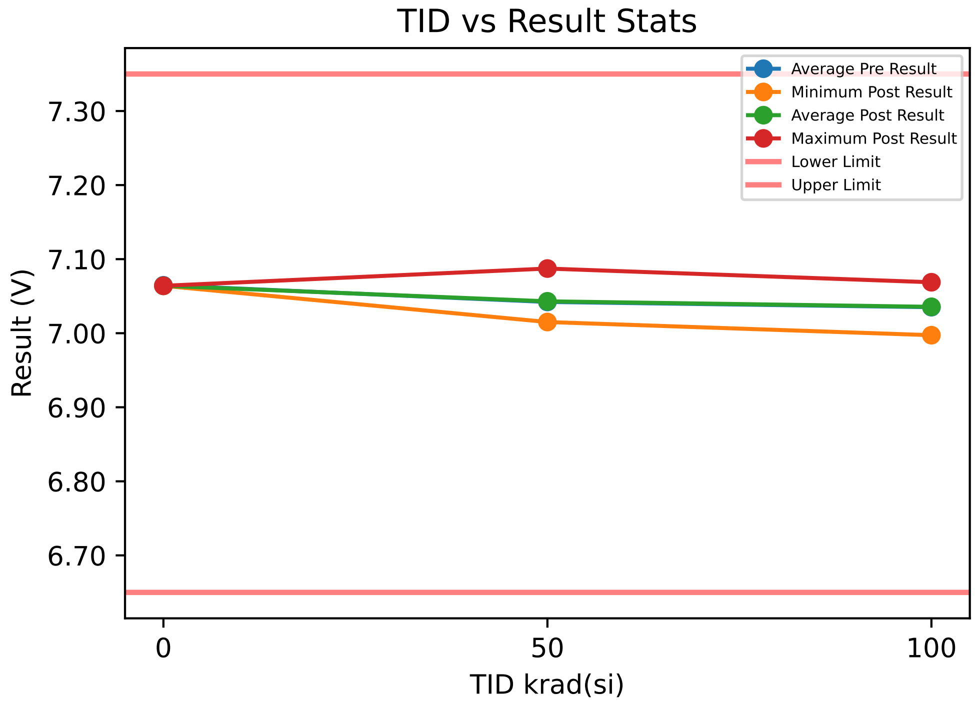
Test Results (Lower Limit = 6.65,
Upper Limit = 7.35 (V))

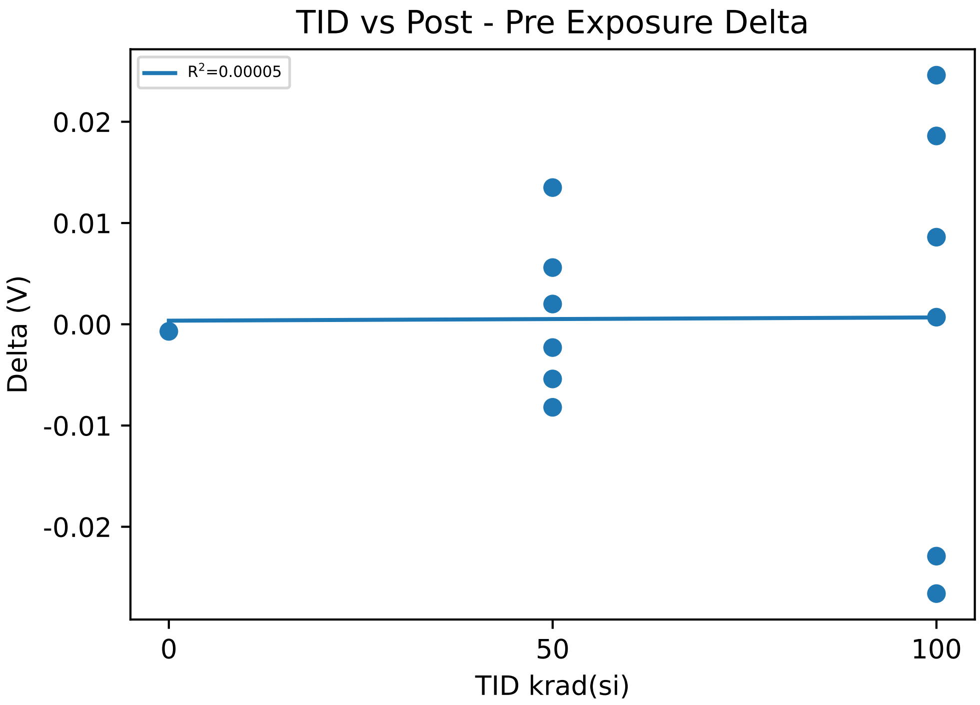
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.057	7.0526	-0.0044
60	50	Biased	7.0207	7.0125	-0.0082
61	50	Biased	7.0379	7.0404	0.0025
63	100	Biased	7.0405	7.0498	0.0093
64	100	Biased	7.0368	7.0137	-0.0231
65	100	Biased	7.0648	7.065	0.0002
66	50	Unbiased	7.023	7.0206	-0.0024
67	50	Unbiased	7.0183	7.0324	0.0141
68	50	Unbiased	7.0787	7.0838	0.0051
69	100	Unbiased	7.0288	7.0484	0.0196
70	100	Unbiased	6.9697	6.9946	0.0249
71	100	Unbiased	7.0518	7.0237	-0.0281
72	0	Control	7.0623	7.0612	-0.0011

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0623	7.0623	7.0623		7.0612	7.0612	7.0612		-0.0011	-0.0011	-0.0011	
50	7.0183	7.0393	7.0787	0.024167	7.0125	7.0404	7.0838	0.025561	-0.0082	0.0011167	0.0141	0.0079492
100	6.9697	7.0321	7.0648	0.033029	6.9946	7.0325	7.065	0.026365	-0.0281	0.00046667	0.0249	0.021966

Device Test: 62.0 V_BP7L PWM 500kHz VIN_14V





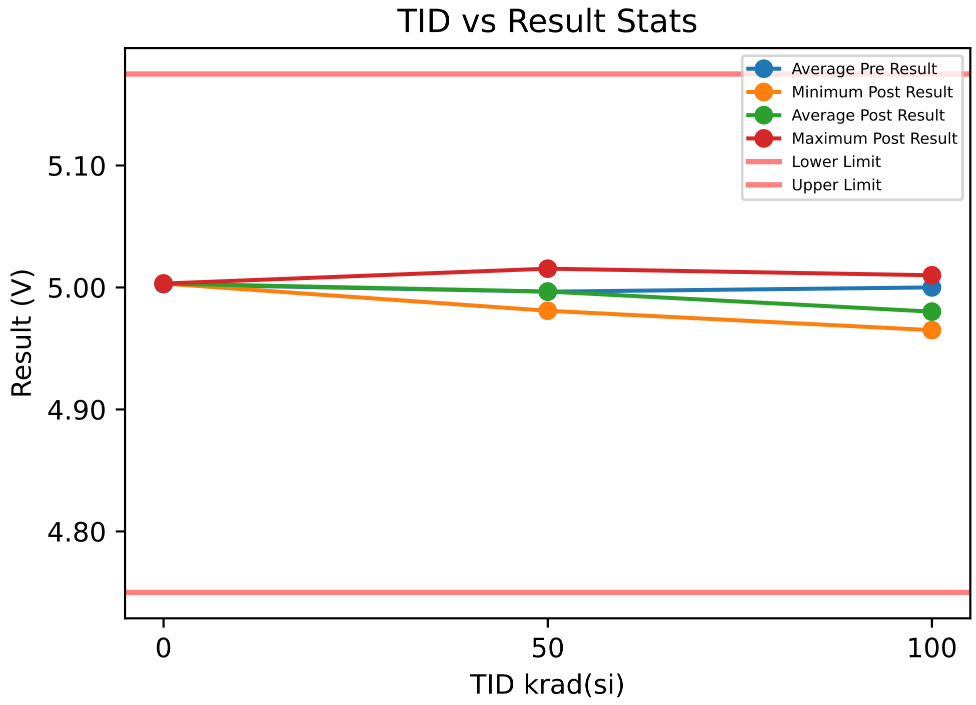
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

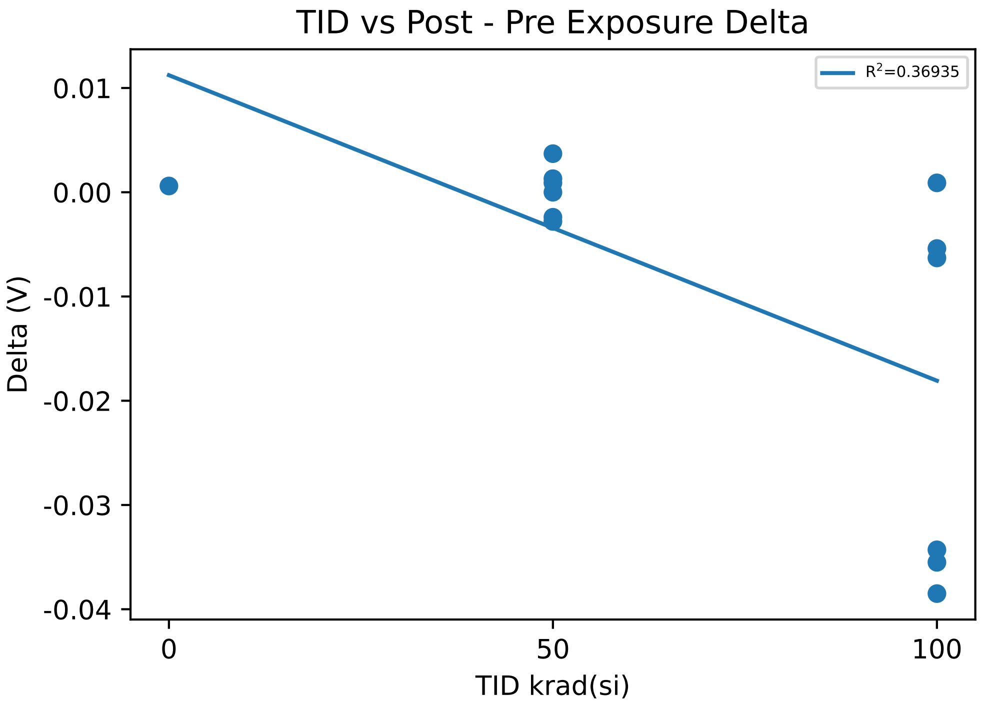
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.06	7.0546	-0.0054
60	50	Biased	7.0233	7.0151	-0.0082
61	50	Biased	7.041	7.043	0.002
63	100	Biased	7.0437	7.0523	0.0086
64	100	Biased	7.0392	7.0163	-0.0229
65	100	Biased	7.0681	7.0688	0.0007
66	50	Unbiased	7.0258	7.0235	-0.0023
67	50	Unbiased	7.0214	7.0349	0.0135
68	50	Unbiased	7.0817	7.0873	0.0056
69	100	Unbiased	7.0322	7.0508	0.0186
70	100	Unbiased	6.9727	6.9973	0.0246
71	100	Unbiased	7.0549	7.0283	-0.0266
72	0	Control	7.0647	7.064	-0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0647	7.0647	7.0647		7.064	7.064	7.064		-0.0007	-0.0007	-0.0007	
50	7.0214	7.0422	7.0817	0.024238	7.0151	7.0431	7.0873	0.025773	-0.0082	0.00086667	0.0135	0.0079346
100	6.9727	7.0351	7.0681	0.033088	6.9973	7.0356	7.0688	0.026476	-0.0266	0.0005	0.0246	0.021242

Device Test: 62.1 V_BP5L PWM 500kHz VIN_14V





Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

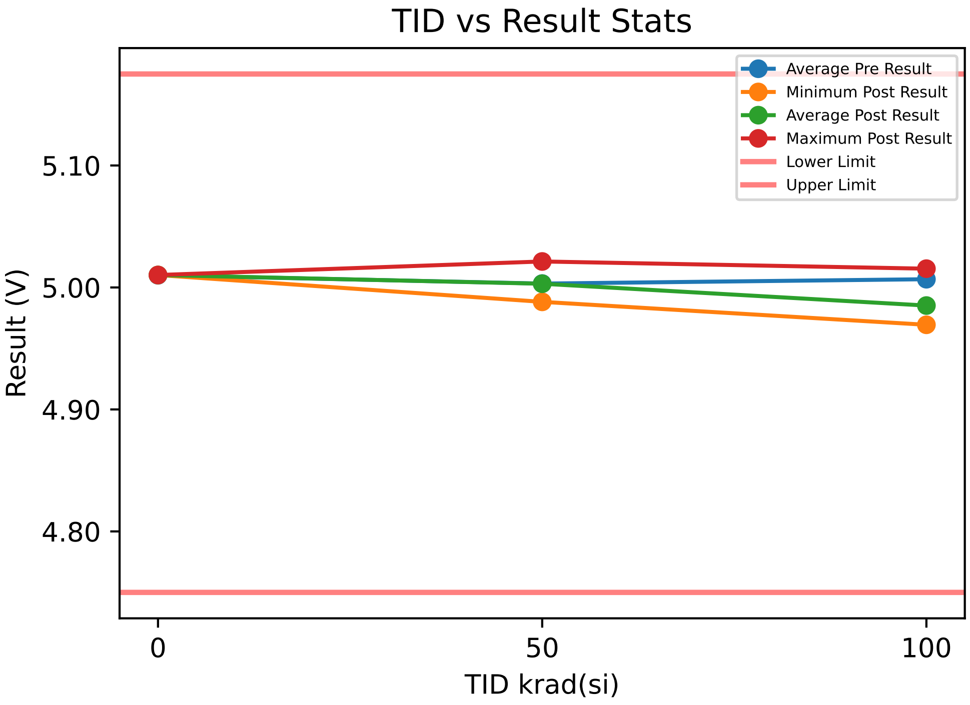
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0015	5.0015	0
60	50	Biased	4.982	4.9857	0.0037
61	50	Biased	5.0066	5.0079	0.0013
63	100	Biased	5.0014	4.9659	-0.0355
64	100	Biased	4.9889	4.9826	-0.0063
65	100	Biased	4.9997	4.9654	-0.0343
66	50	Unbiased	4.9837	4.9809	-0.0028
67	50	Unbiased	4.9877	4.9886	0.0009
68	50	Unbiased	5.0178	5.0154	-0.0024
69	100	Unbiased	5.0154	5.01	-0.0054
70	100	Unbiased	4.9913	4.9922	0.0009
71	100	Unbiased	5.0035	4.965	-0.0385
72	0	Control	5.0026	5.0032	0.0006

Test Statistics (V)

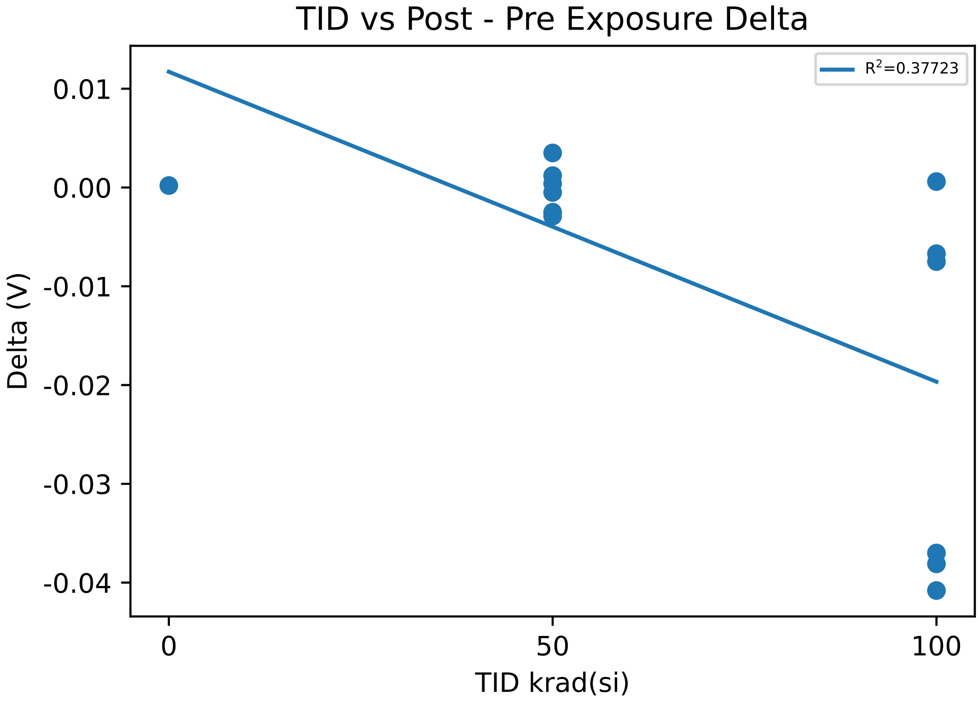
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0026	5.0026	5.0026		5.0032	5.0032	5.0032		0.0006	0.0006	0.0006	
50	4.982	4.9966	5.0178	0.014368	4.9809	4.9967	5.0154	0.013671	-0.0028	0.00011667	0.0037	0.0024376
100	4.9889	5	5.0154	0.0094906	4.965	4.9802	5.01	0.018398	-0.0385	-0.01985	0.0009	0.018025

Device Test: 62.10 V_BP5L PWM 5MHz VIN_14V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



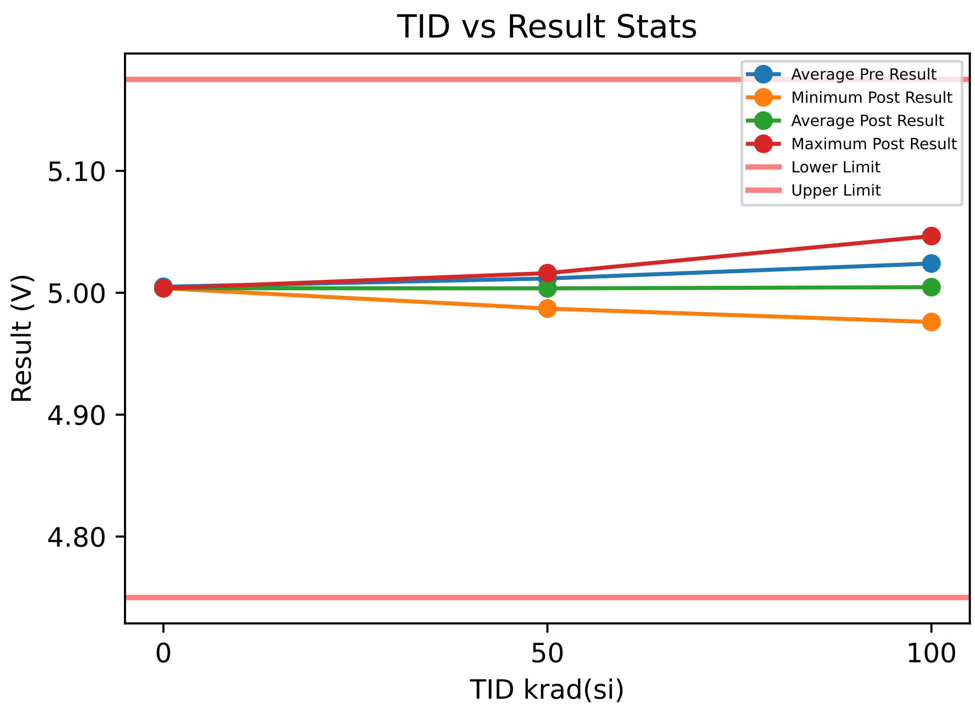
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

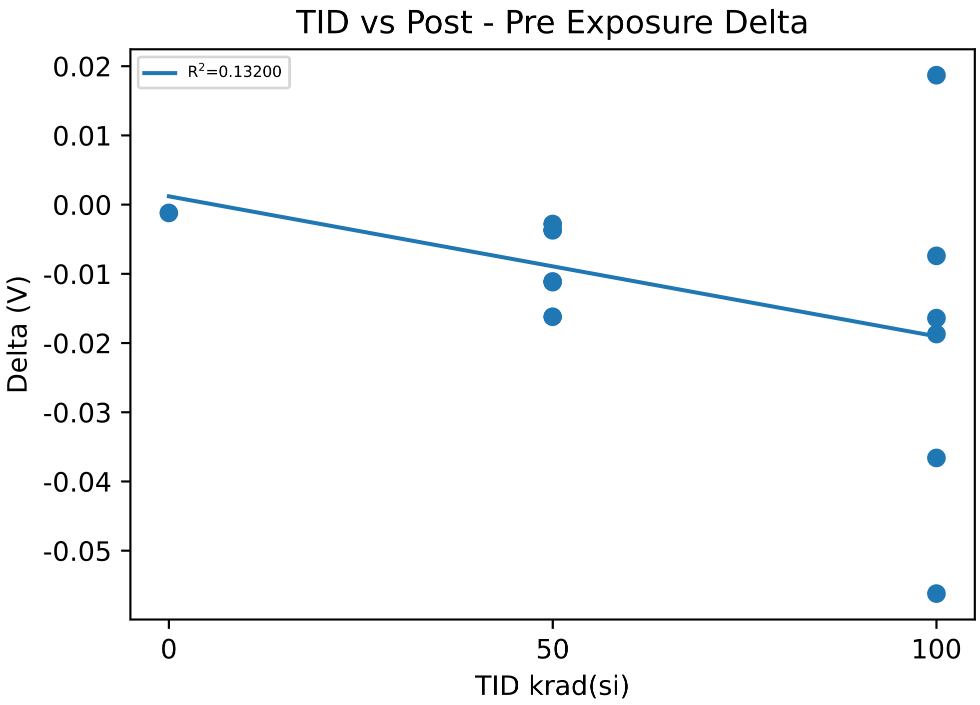
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.008	5.0075	-0.0005
60	50	Biased	4.9882	4.9917	0.0035
61	50	Biased	5.0134	5.0146	0.0012
63	100	Biased	5.0077	4.9696	-0.0381
64	100	Biased	4.9956	4.9881	-0.0075
65	100	Biased	5.0066	4.9696	-0.037
66	50	Unbiased	4.9907	4.9882	-0.0025
67	50	Unbiased	4.9946	4.995	0.0004
68	50	Unbiased	5.0242	5.0213	-0.0029
69	100	Unbiased	5.0221	5.0154	-0.0067
70	100	Unbiased	4.9983	4.9989	0.0006
71	100	Unbiased	5.0102	4.9694	-0.0408
72	0	Control	5.01	5.0102	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.01	5.01	5.01		5.0102	5.0102	5.0102		0.0002	0.0002	0.0002	
50	4.9882	5.0032	5.0242	0.014306	4.9882	5.003	5.0213	0.01342	-0.0029	-0.00013333	0.0035	0.0023939
100	4.9956	5.0068	5.0221	0.0094252	4.9694	4.9852	5.0154	0.019207	-0.0408	-0.021583	0.0006	0.01893

Device Test: 62.11 V_BP5H PWM 5MHz VIN_14V





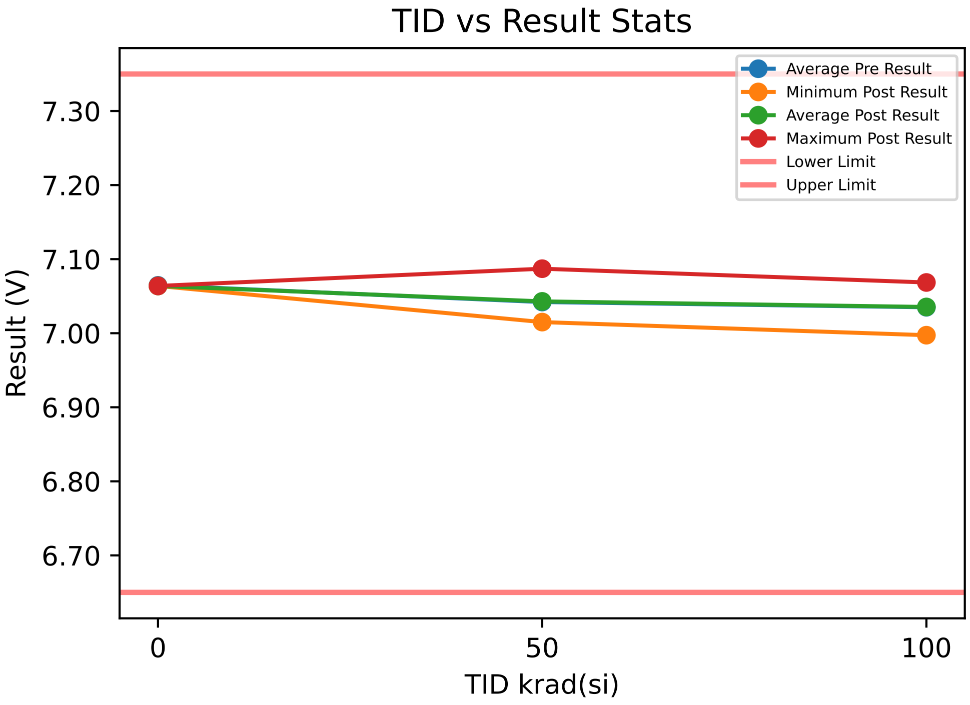
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

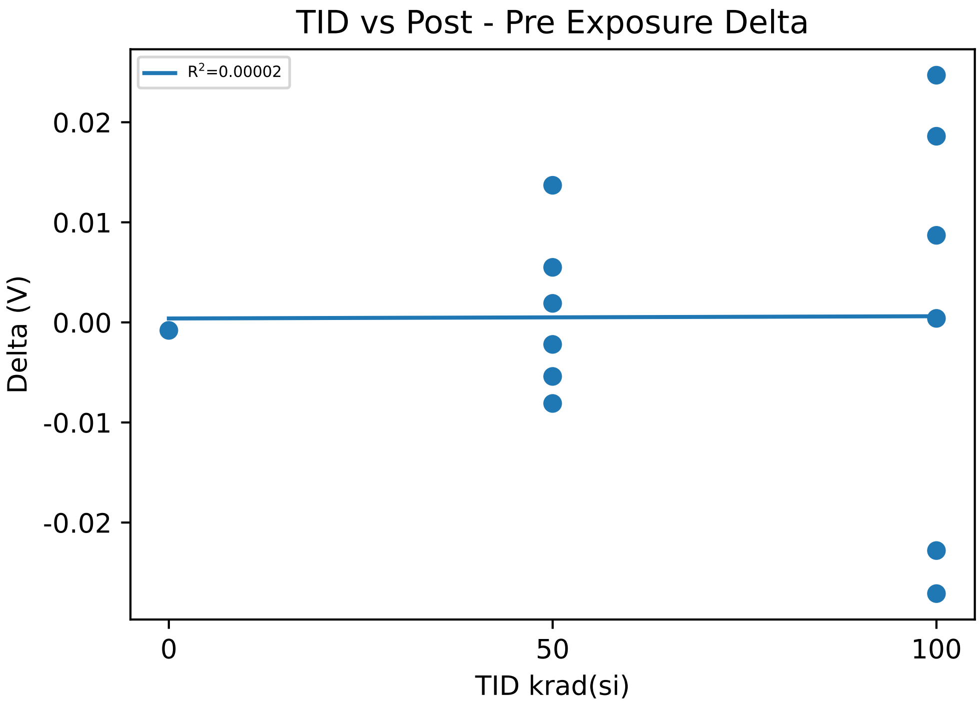
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0153	5.0116	-0.0037
60	50	Biased	5.0054	4.9942	-0.0112
61	50	Biased	5.0164	5.0136	-0.0028
63	100	Biased	5.0104	4.9917	-0.0187
64	100	Biased	5.0356	4.999	-0.0366
65	100	Biased	5.0319	5.0245	-0.0074
66	50	Unbiased	4.9981	4.987	-0.0111
67	50	Unbiased	5.0028	4.9991	-0.0037
68	50	Unbiased	5.0323	5.0161	-0.0162
69	100	Unbiased	5.0322	4.976	-0.0562
70	100	Unbiased	5.006	4.9896	-0.0164
71	100	Unbiased	5.0278	5.0465	0.0187
72	0	Control	5.0049	5.0037	-0.0012

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0049	5.0049	5.0049		5.0037	5.0037	5.0037		-0.0012	-0.0012	-0.0012	
50	4.9981	5.0117	5.0323	0.012355	4.987	5.0036	5.0161	0.011869	-0.0162	-0.0081167	-0.0028	0.005496
100	5.006	5.024	5.0356	0.012551	4.976	5.0046	5.0465	0.026047	-0.0562	-0.019433	0.0187	0.025515

Device Test: 62.12 V_BP7L IIM 500kHz VIN_14V





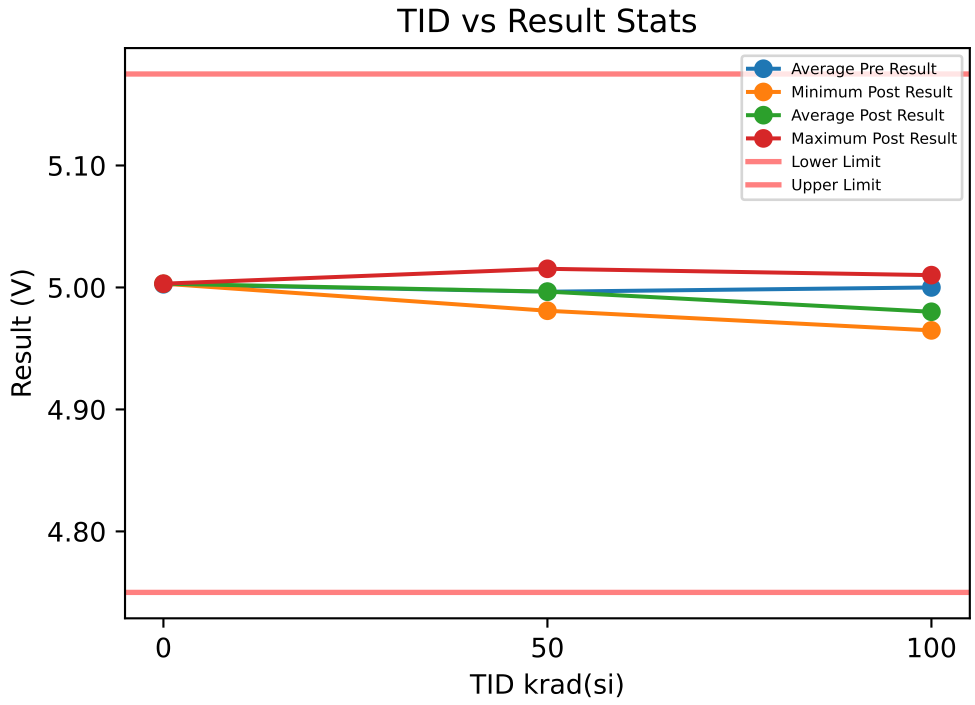
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

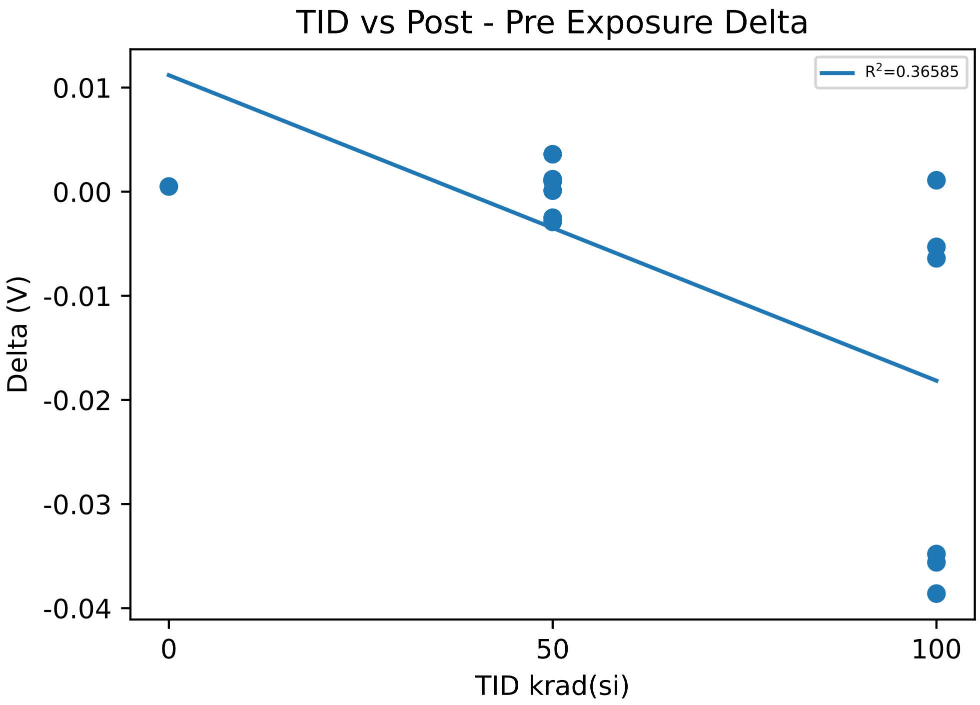
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0598	7.0544	-0.0054
60	50	Biased	7.0231	7.015	-0.0081
61	50	Biased	7.0411	7.043	0.0019
63	100	Biased	7.0437	7.0524	0.0087
64	100	Biased	7.0391	7.0163	-0.0228
65	100	Biased	7.0681	7.0685	0.0004
66	50	Unbiased	7.0256	7.0234	-0.0022
67	50	Unbiased	7.0212	7.0349	0.0137
68	50	Unbiased	7.0816	7.0871	0.0055
69	100	Unbiased	7.0319	7.0505	0.0186
70	100	Unbiased	6.9726	6.9973	0.0247
71	100	Unbiased	7.0547	7.0276	-0.0271
72	0	Control	7.0646	7.0638	-0.0008

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0646	7.0646	7.0646		7.0638	7.0638	7.0638		-0.0008	-0.0008	-0.0008	
50	7.0212	7.0421	7.0816	0.024268	7.015	7.043	7.0871	0.025724	-0.0081	0.0009	0.0137	0.0079536
100	6.9726	7.035	7.0681	0.033105	6.9973	7.0354	7.0685	0.026419	-0.0271	0.00041667	0.0247	0.021378

Device Test: 62.13 V_BP5L IIM 500kHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

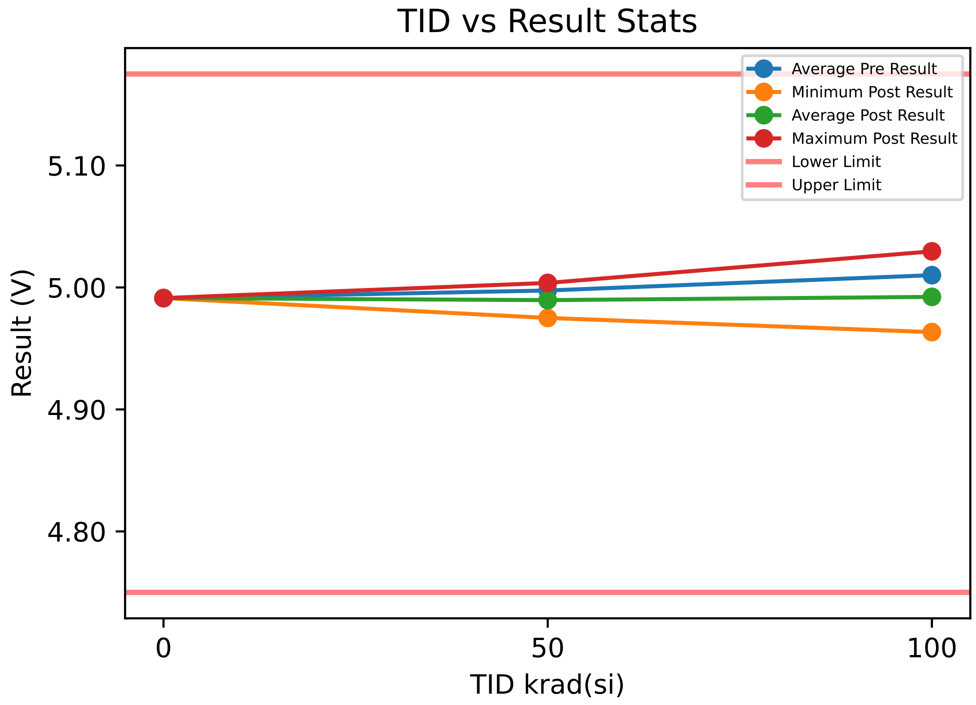
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0014	5.0015	0.0001
60	50	Biased	4.9819	4.9855	0.0036
61	50	Biased	5.0066	5.0078	0.0012
63	100	Biased	5.0014	4.9658	-0.0356
64	100	Biased	4.9888	4.9824	-0.0064
65	100	Biased	4.9996	4.9648	-0.0348
66	50	Unbiased	4.9838	4.9809	-0.0029
67	50	Unbiased	4.9876	4.9886	0.001
68	50	Unbiased	5.0178	5.0153	-0.0025
69	100	Unbiased	5.0154	5.0101	-0.0053
70	100	Unbiased	4.9913	4.9924	0.0011
71	100	Unbiased	5.0035	4.9649	-0.0386
72	0	Control	5.0026	5.0031	0.0005

Test Statistics (V)

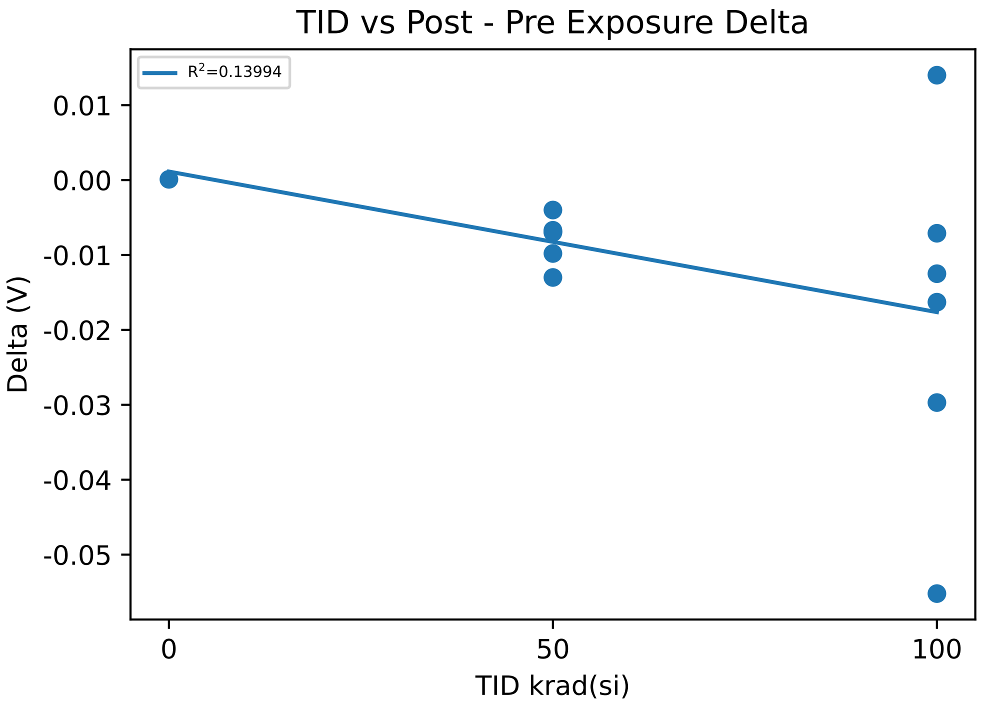
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0026	5.0026	5.0026		5.0031	5.0031	5.0031		0.0005	0.0005	0.0005	
50	4.9819	4.9965	5.0178	0.014376	4.9809	4.9966	5.0153	0.013659	-0.0029	8.3333e-05	0.0036	0.0024506
100	4.9888	5	5.0154	0.0095148	4.9648	4.9801	5.0101	0.018581	-0.0386	-0.019933	0.0011	0.018191

Device Test: 62.14 V_BP5H IIM 500kHz VIN_14V


TID vs Result Stats

Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

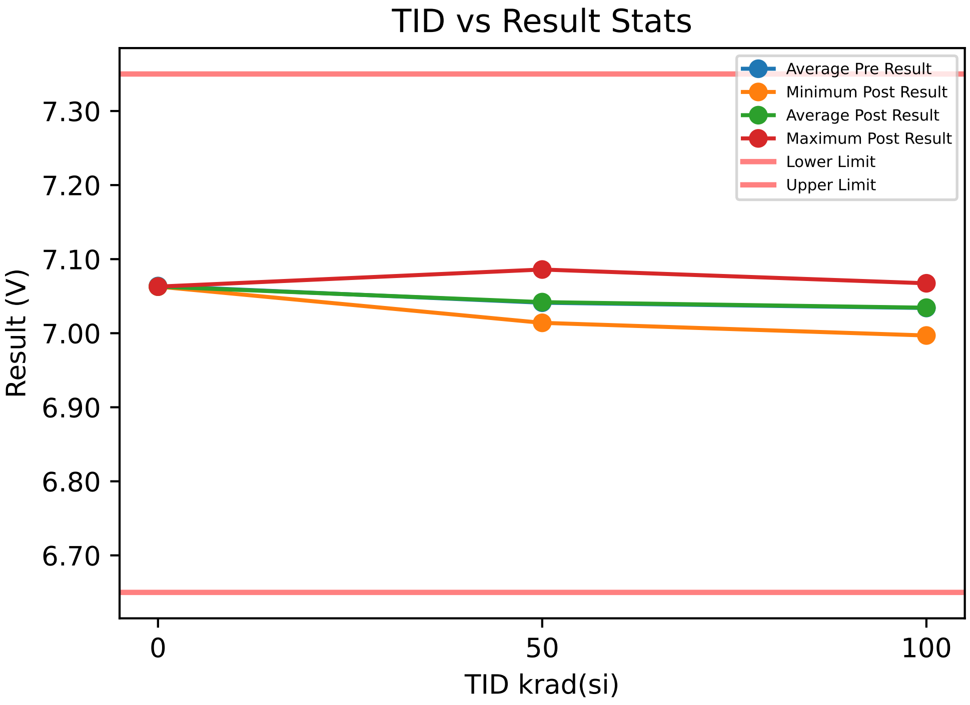
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0021	4.9954	-0.0067
60	50	Biased	4.9892	4.9823	-0.0069
61	50	Biased	5.0018	4.9978	-0.004
63	100	Biased	4.9974	4.9811	-0.0163
64	100	Biased	5.0194	4.9897	-0.0297
65	100	Biased	5.0197	5.0126	-0.0071
66	50	Unbiased	4.9848	4.975	-0.0098
67	50	Unbiased	4.9905	4.9835	-0.007
68	50	Unbiased	5.0167	5.0037	-0.013
69	100	Unbiased	5.0186	4.9634	-0.0552
70	100	Unbiased	4.9897	4.9772	-0.0125
71	100	Unbiased	5.0156	5.0296	0.014
72	0	Control	4.9912	4.9913	0.0001

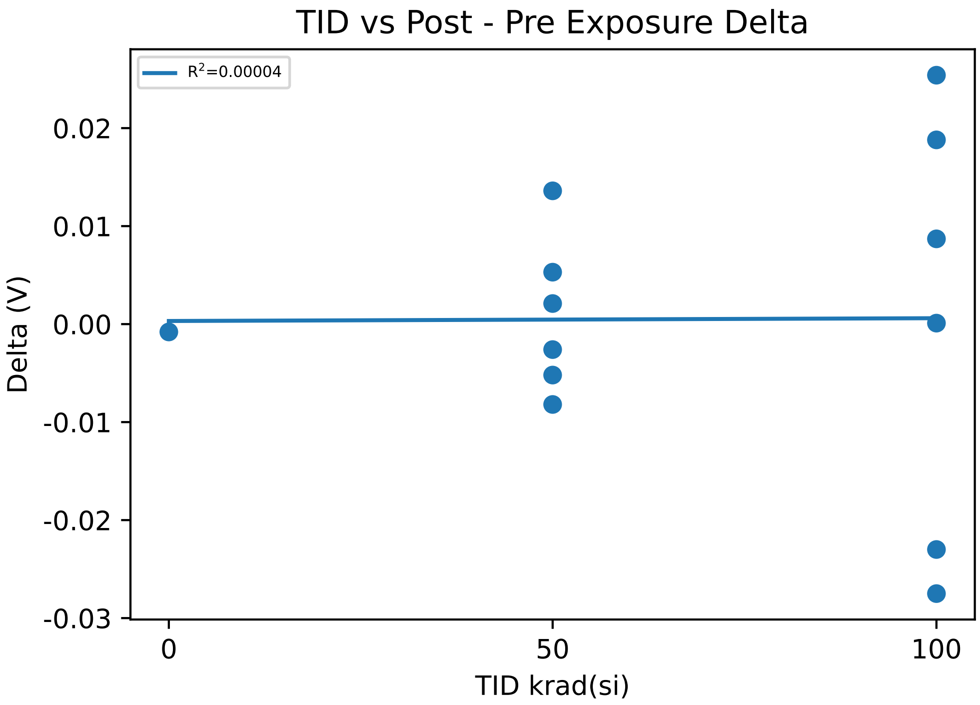

TID vs Post - Pre Exposure Delta

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9912	4.9912	4.9912		4.9913	4.9913	4.9913		0.0001	0.0001	0.0001	
50	4.9848	4.9975	5.0167	0.011726	4.975	4.9896	5.0037	0.010985	-0.013	-0.0079	-0.004	0.003101
100	4.9897	5.0101	5.0197	0.013104	4.9634	4.9923	5.0296	0.02449	-0.0552	-0.0178	0.014	0.023223

Device Test: 62.15 V_BP7L IIM 1MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

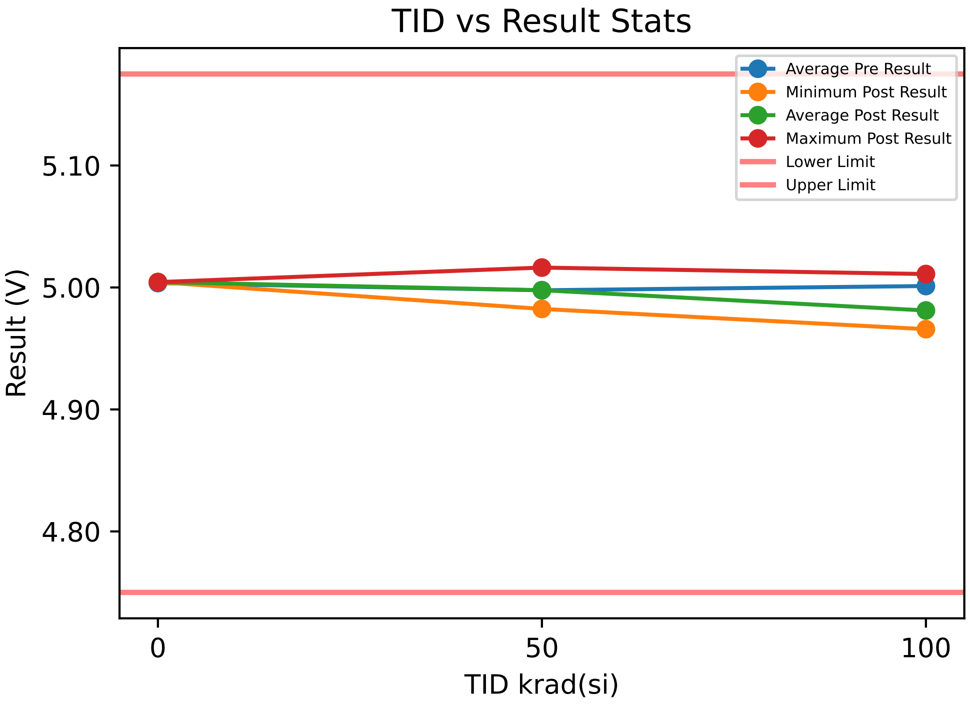
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

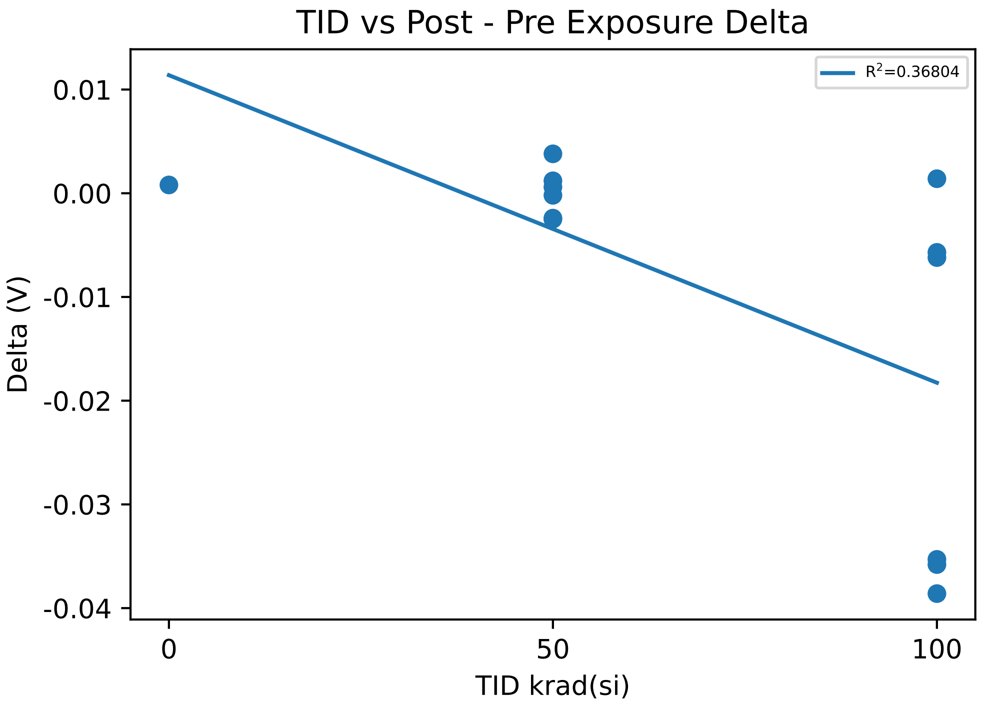
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0589	7.0537	-0.0052
60	50	Biased	7.0222	7.014	-0.0082
61	50	Biased	7.04	7.0421	0.0021
63	100	Biased	7.0427	7.0514	0.0087
64	100	Biased	7.0382	7.0152	-0.023
65	100	Biased	7.0673	7.0674	0.0001
66	50	Unbiased	7.0248	7.0222	-0.0026
67	50	Unbiased	7.0203	7.0339	0.0136
68	50	Unbiased	7.0807	7.086	0.0053
69	100	Unbiased	7.0309	7.0497	0.0188
70	100	Unbiased	6.9715	6.9969	0.0254
71	100	Unbiased	7.0536	7.0261	-0.0275
72	0	Control	7.0637	7.0629	-0.0008

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0637	7.0637	7.0637		7.0629	7.0629	7.0629		-0.0008	-0.0008	-0.0008	
50	7.0203	7.0411	7.0807	0.024256	7.014	7.042	7.086	0.025747	-0.0082	0.00083333	0.0136	0.0079289
100	6.9715	7.034	7.0673	0.033173	6.9969	7.0344	7.0674	0.02629	-0.0275	0.00041667	0.0254	0.021719

Device Test: 62.16 V_BP5L IIM 1MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

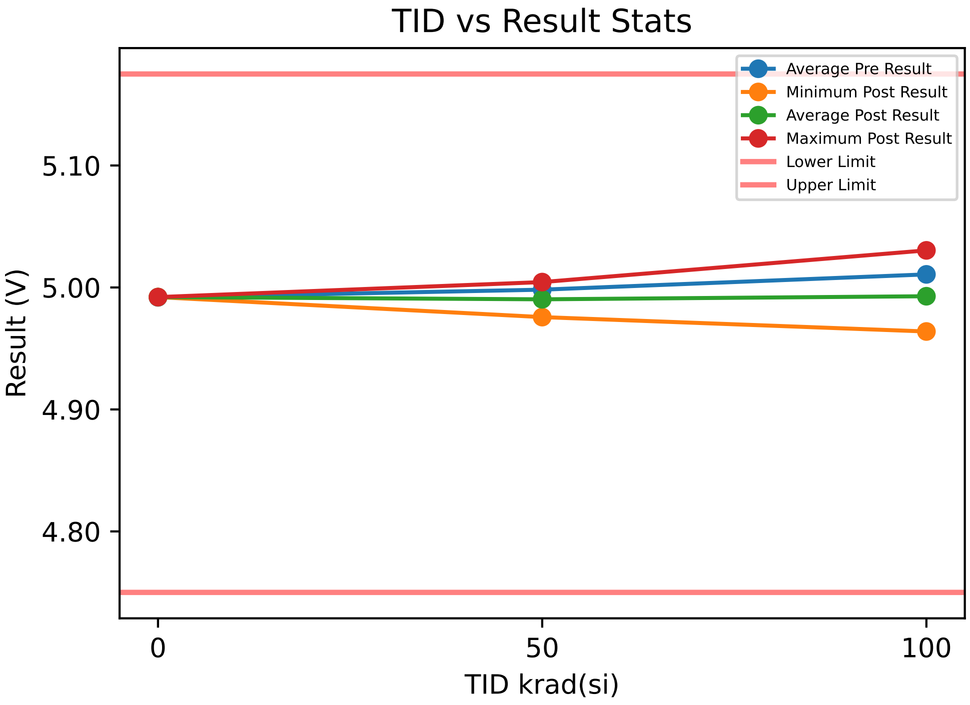
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

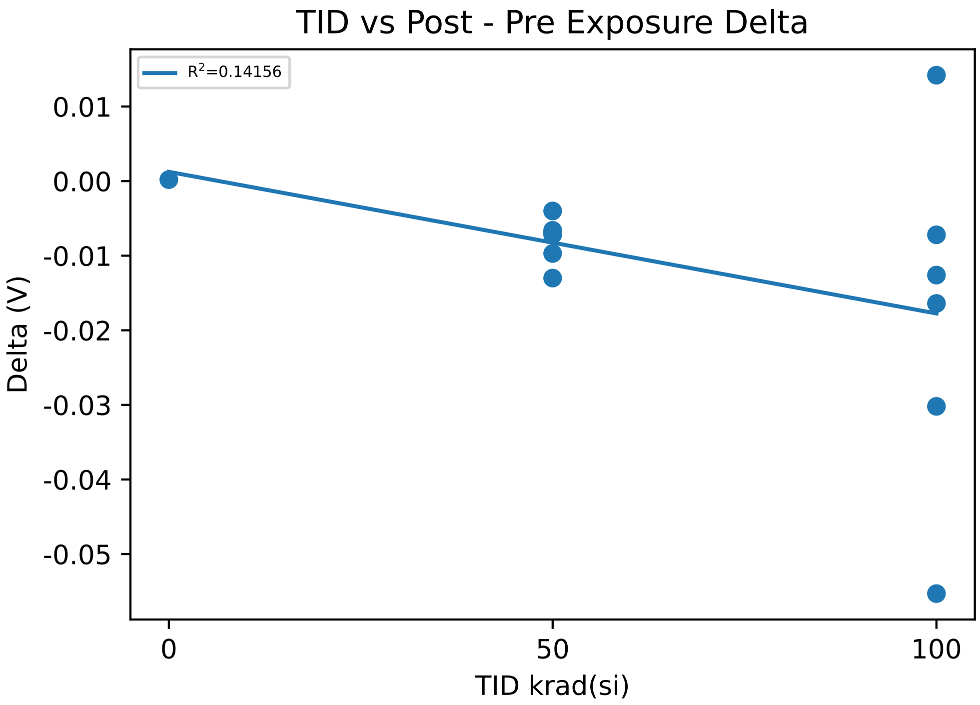
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0028	5.0026	-0.0002
60	50	Biased	4.9828	4.9866	0.0038
61	50	Biased	5.0078	5.009	0.0012
63	100	Biased	5.0025	4.9667	-0.0358
64	100	Biased	4.9897	4.9835	-0.0062
65	100	Biased	5.0011	4.9658	-0.0353
66	50	Unbiased	4.9849	4.9824	-0.0025
67	50	Unbiased	4.9891	4.9897	0.0006
68	50	Unbiased	5.0187	5.0163	-0.0024
69	100	Unbiased	5.0167	5.011	-0.0057
70	100	Unbiased	4.9924	4.9938	0.0014
71	100	Unbiased	5.0046	4.966	-0.0386
72	0	Control	5.0036	5.0044	0.0008

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0036	5.0036	5.0036		5.0044	5.0044	5.0044		0.0008	0.0008	0.0008	
50	4.9828	4.9977	5.0187	0.014345	4.9824	4.9978	5.0163	0.013557	-0.0025	8.3333e-05	0.0038	0.0023769
100	4.9897	5.0012	5.0167	0.0096249	4.9658	4.9811	5.011	0.018604	-0.0386	-0.020033	0.0014	0.018344

Device Test: 62.17 V_BP5H IIM 1MHz VIN_14V





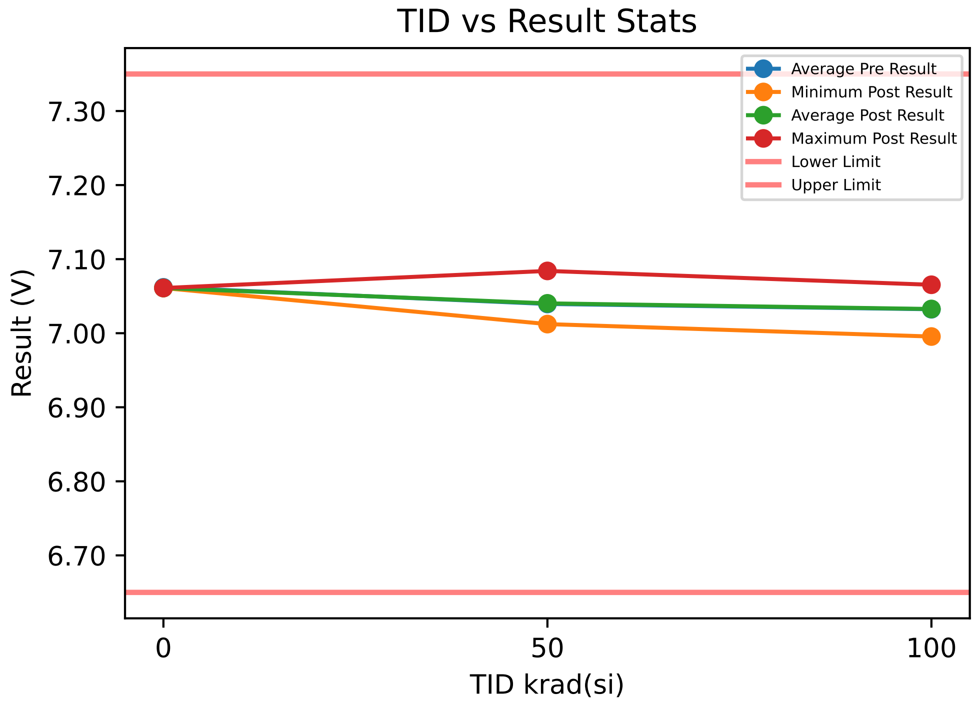
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

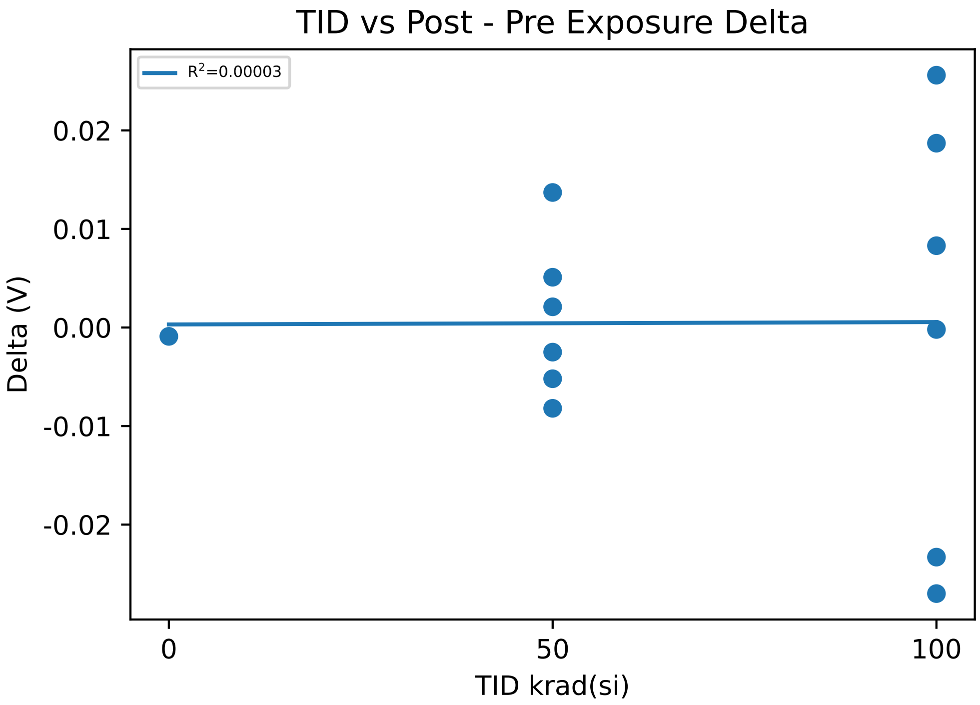
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0027	4.9961	-0.0066
60	50	Biased	4.9897	4.9828	-0.0069
61	50	Biased	5.0026	4.9986	-0.004
63	100	Biased	4.998	4.9816	-0.0164
64	100	Biased	5.0201	4.9899	-0.0302
65	100	Biased	5.0204	5.0132	-0.0072
66	50	Unbiased	4.9854	4.9757	-0.0097
67	50	Unbiased	4.9913	4.9841	-0.0072
68	50	Unbiased	5.0174	5.0044	-0.013
69	100	Unbiased	5.0192	4.9639	-0.0553
70	100	Unbiased	4.9904	4.9778	-0.0126
71	100	Unbiased	5.0162	5.0304	0.0142
72	0	Control	4.9919	4.9921	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9919	4.9919	4.9919		4.9921	4.9921	4.9921		0.0002	0.0002	0.0002	
50	4.9854	4.9982	5.0174	0.011764	4.9757	4.9903	5.0044	0.011038	-0.013	-0.0079	-0.004	0.0030867
100	4.9904	5.0107	5.0204	0.013102	4.9639	4.9928	5.0304	0.024593	-0.0553	-0.017917	0.0142	0.023346

Device Test: 62.18 V_BP7L IIM 2MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

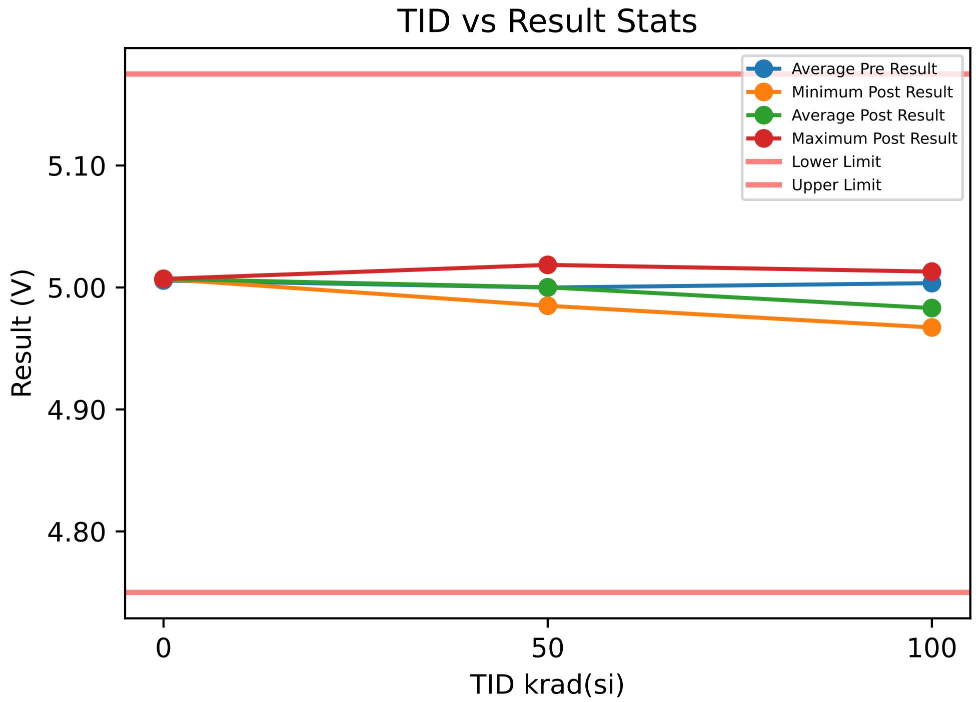
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

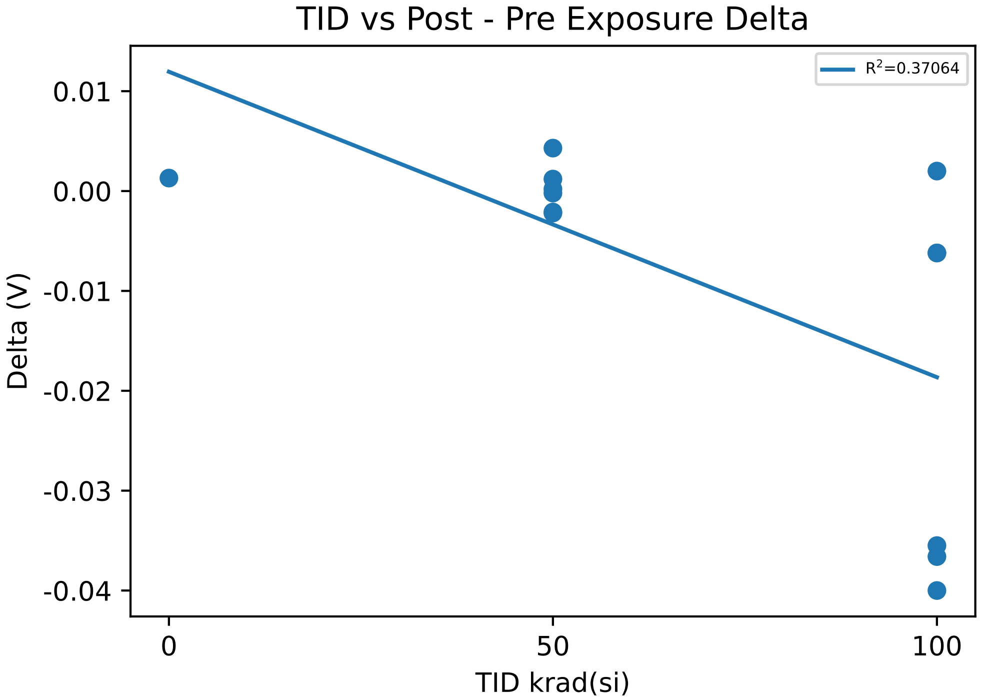
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0572	7.052	-0.0052
60	50	Biased	7.0205	7.0123	-0.0082
61	50	Biased	7.0384	7.0405	0.0021
63	100	Biased	7.0411	7.0494	0.0083
64	100	Biased	7.0365	7.0132	-0.0233
65	100	Biased	7.0656	7.0654	-0.0002
66	50	Unbiased	7.0231	7.0206	-0.0025
67	50	Unbiased	7.0187	7.0324	0.0137
68	50	Unbiased	7.079	7.0841	0.0051
69	100	Unbiased	7.0292	7.0479	0.0187
70	100	Unbiased	6.9699	6.9955	0.0256
71	100	Unbiased	7.0518	7.0248	-0.027
72	0	Control	7.0619	7.061	-0.0009

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0619	7.0619	7.0619		7.061	7.061	7.061		-0.0009	-0.0009	-0.0009	
50	7.0187	7.0395	7.079	0.024238	7.0123	7.0403	7.0841	0.025651	-0.0082	0.00083333	0.0137	0.0079306
100	6.9699	7.0324	7.0656	0.033129	6.9955	7.0327	7.0654	0.026099	-0.027	0.00035	0.0256	0.021657

Device Test: 62.19 V_BP5L IIM 2MHz VIN_14V





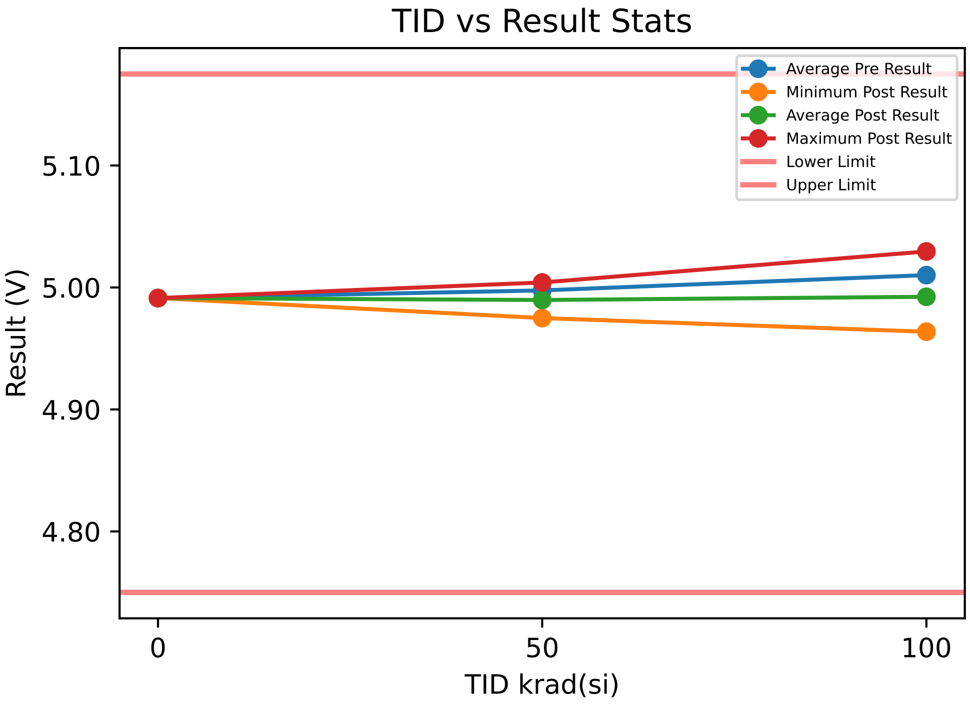
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0053	5.0051	-0.0002
60	50	Biased	4.9846	4.9889	0.0043
61	50	Biased	5.0102	5.0114	0.0012
63	100	Biased	5.0049	4.9683	-0.0366
64	100	Biased	4.9916	4.9854	-0.0062
65	100	Biased	5.0038	4.9683	-0.0355
66	50	Unbiased	4.9871	4.985	-0.0021
67	50	Unbiased	4.9917	4.9919	0.0002
68	50	Unbiased	5.0207	5.0185	-0.0022
69	100	Unbiased	5.0192	5.013	-0.0062
70	100	Unbiased	4.9945	4.9965	0.002
71	100	Unbiased	5.0072	4.9672	-0.04
72	0	Control	5.0057	5.007	0.0013

Test Statistics (V)

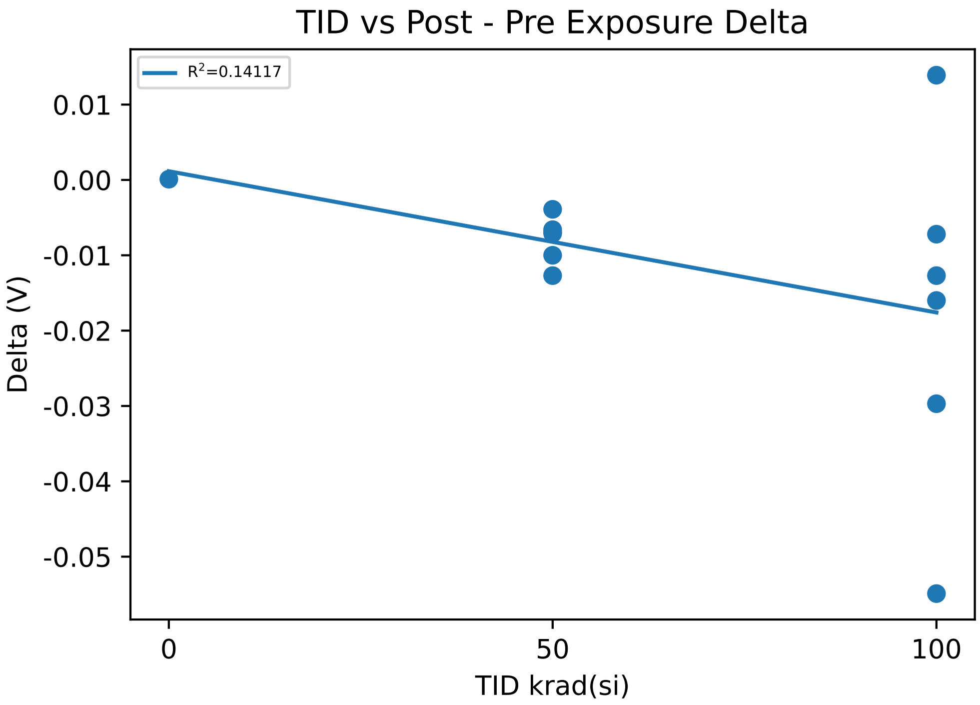
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0057	5.0057	5.0057		5.007	5.007	5.007		0.0013	0.0013	0.0013	
50	4.9846	4.9999	5.0207	0.014374	4.985	5.0001	5.0185	0.013505	-0.0022	0.0002	0.0043	0.0024091
100	4.9916	5.0035	5.0192	0.0098472	4.9672	4.9831	5.013	0.018814	-0.04	-0.020417	0.002	0.018866

Device Test: 62.2 V_BP5H PWM 500kHz VIN_14V



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

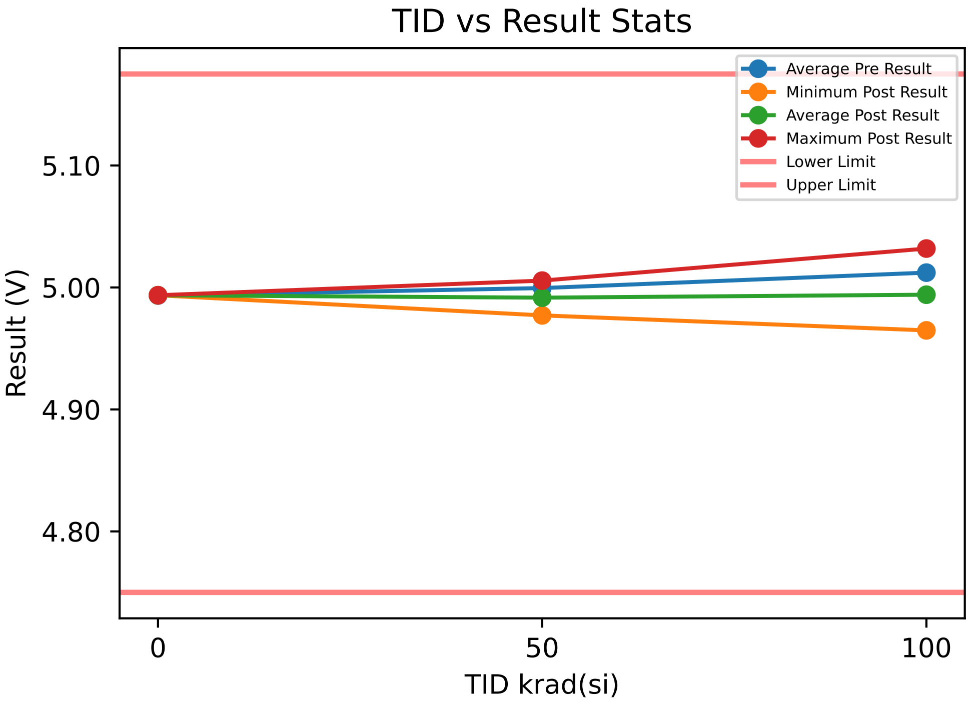
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0022	4.9956	-0.0066
60	50	Biased	4.9891	4.9822	-0.0069
61	50	Biased	5.0019	4.998	-0.0039
63	100	Biased	4.9973	4.9813	-0.016
64	100	Biased	5.0196	4.9899	-0.0297
65	100	Biased	5.0198	5.0126	-0.0072
66	50	Unbiased	4.9849	4.9749	-0.01
67	50	Unbiased	4.9906	4.9835	-0.0071
68	50	Unbiased	5.0168	5.0041	-0.0127
69	100	Unbiased	5.0186	4.9637	-0.0549
70	100	Unbiased	4.9898	4.9771	-0.0127
71	100	Unbiased	5.0156	5.0295	0.0139
72	0	Control	4.9912	4.9913	0.0001

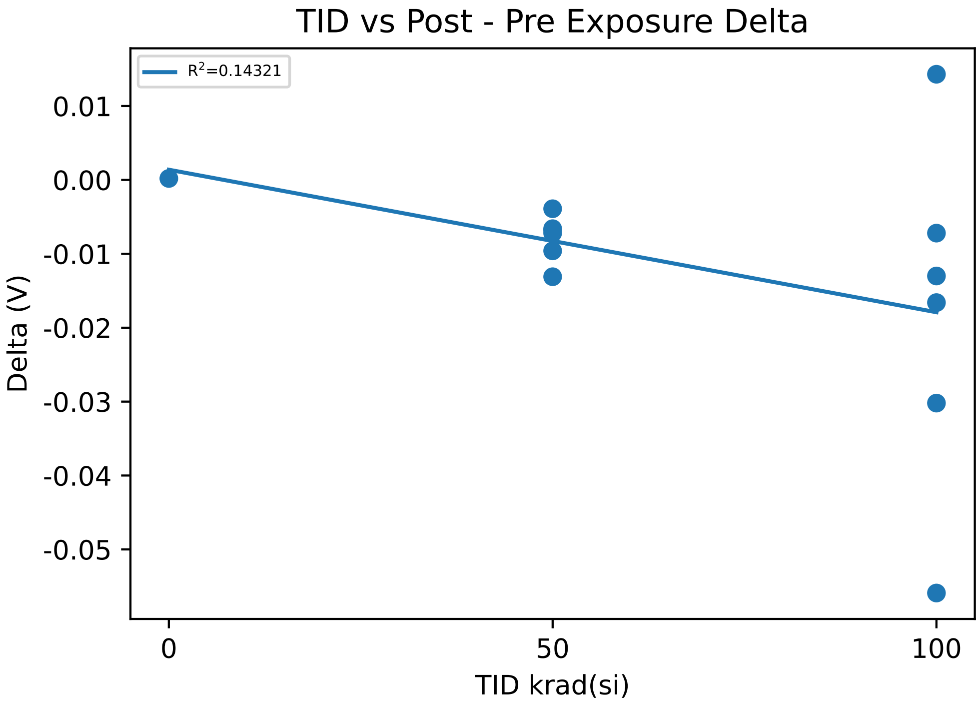


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9912	4.9912	4.9912		4.9913	4.9913	4.9913		0.0001	0.0001	0.0001	
50	4.9849	4.9976	5.0168	0.011754	4.9749	4.9897	5.0041	0.011178	-0.0127	-0.0078667	-0.0039	0.0030585
100	4.9898	5.0101	5.0198	0.013136	4.9637	4.9924	5.0295	0.024379	-0.0549	-0.017767	0.0139	0.023085

Device Test: 62.20 V_BP5H IIM 2MHz VIN_14V





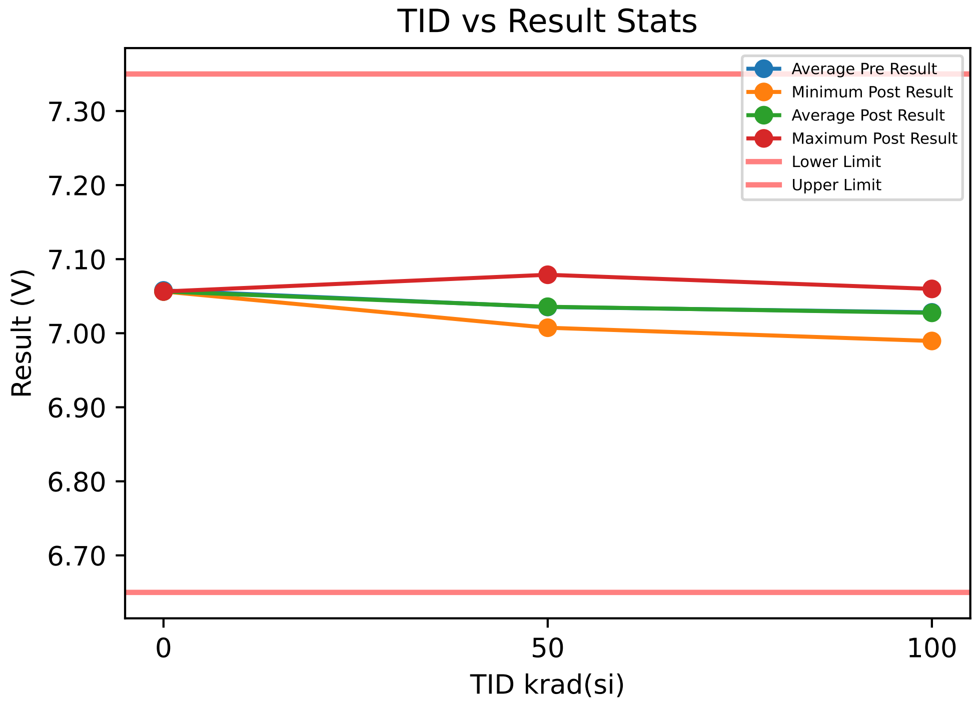
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

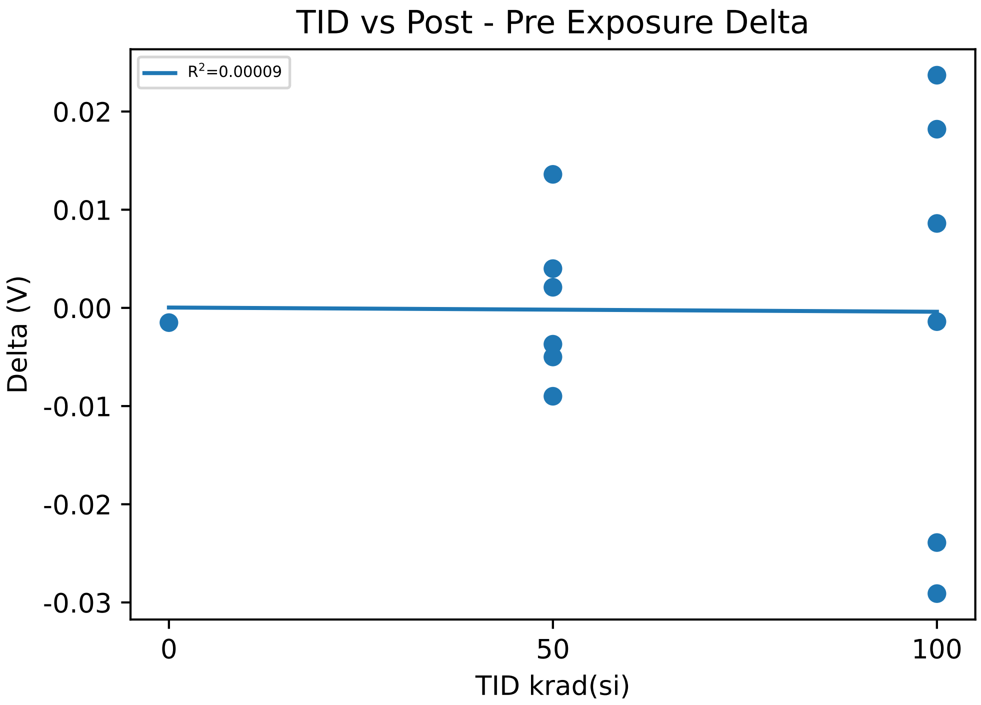
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.004	4.9974	-0.0066
60	50	Biased	4.991	4.9842	-0.0068
61	50	Biased	5.0039	5	-0.0039
63	100	Biased	4.9995	4.9829	-0.0166
64	100	Biased	5.0213	4.9911	-0.0302
65	100	Biased	5.0218	5.0146	-0.0072
66	50	Unbiased	4.9867	4.9771	-0.0096
67	50	Unbiased	4.9927	4.9855	-0.0072
68	50	Unbiased	5.0187	5.0056	-0.0131
69	100	Unbiased	5.0207	4.9648	-0.0559
70	100	Unbiased	4.992	4.979	-0.013
71	100	Unbiased	5.0176	5.0319	0.0143
72	0	Control	4.9934	4.9936	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9934	4.9934	4.9934		4.9936	4.9936	4.9936		0.0002	0.0002	0.0002	
50	4.9867	4.9995	5.0187	0.011752	4.9771	4.9916	5.0056	0.010976	-0.0131	-0.0078667	-0.0039	0.0031405
100	4.992	5.0122	5.0218	0.013005	4.9648	4.9941	5.0319	0.024779	-0.0559	-0.0181	0.0143	0.023546

Device Test: 62.21 V_BP7L IIM 5MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

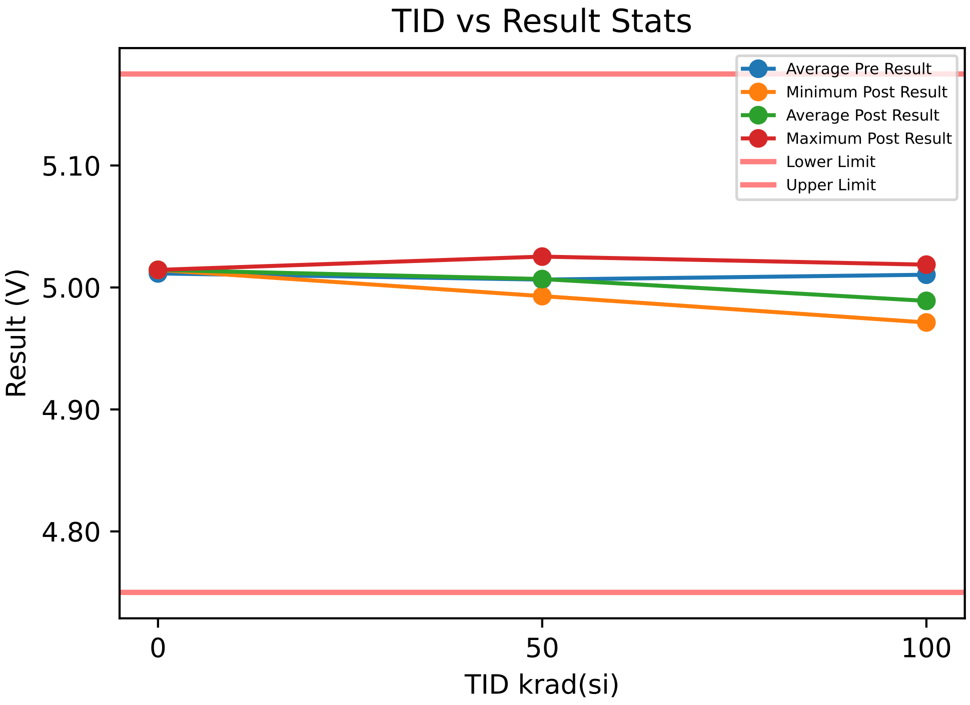
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

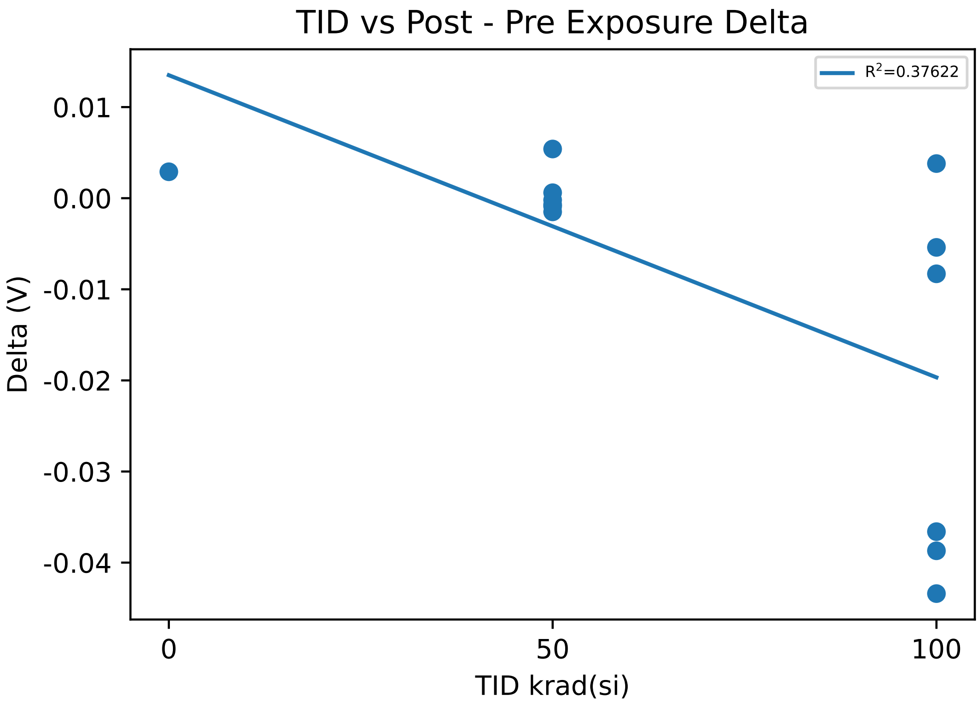
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.053	7.048	-0.005
60	50	Biased	7.0164	7.0074	-0.009
61	50	Biased	7.0344	7.0365	0.0021
63	100	Biased	7.0369	7.0455	0.0086
64	100	Biased	7.0325	7.0086	-0.0239
65	100	Biased	7.0612	7.0598	-0.0014
66	50	Unbiased	7.0192	7.0155	-0.0037
67	50	Unbiased	7.0144	7.028	0.0136
68	50	Unbiased	7.0749	7.0789	0.004
69	100	Unbiased	7.025	7.0432	0.0182
70	100	Unbiased	6.9658	6.9895	0.0237
71	100	Unbiased	7.0474	7.0183	-0.0291
72	0	Control	7.0578	7.0563	-0.0015

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0578	7.0578	7.0578		7.0563	7.0563	7.0563		-0.0015	-0.0015	-0.0015	
50	7.0144	7.0354	7.0749	0.02423	7.0074	7.0357	7.0789	0.025637	-0.009	0.00033333	0.0136	0.0080547
100	6.9658	7.0281	7.0612	0.033033	6.9895	7.0275	7.0598	0.026456	-0.0291	-0.00065	0.0237	0.021837

Device Test: 62.22 V_BP5L IIM 5MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

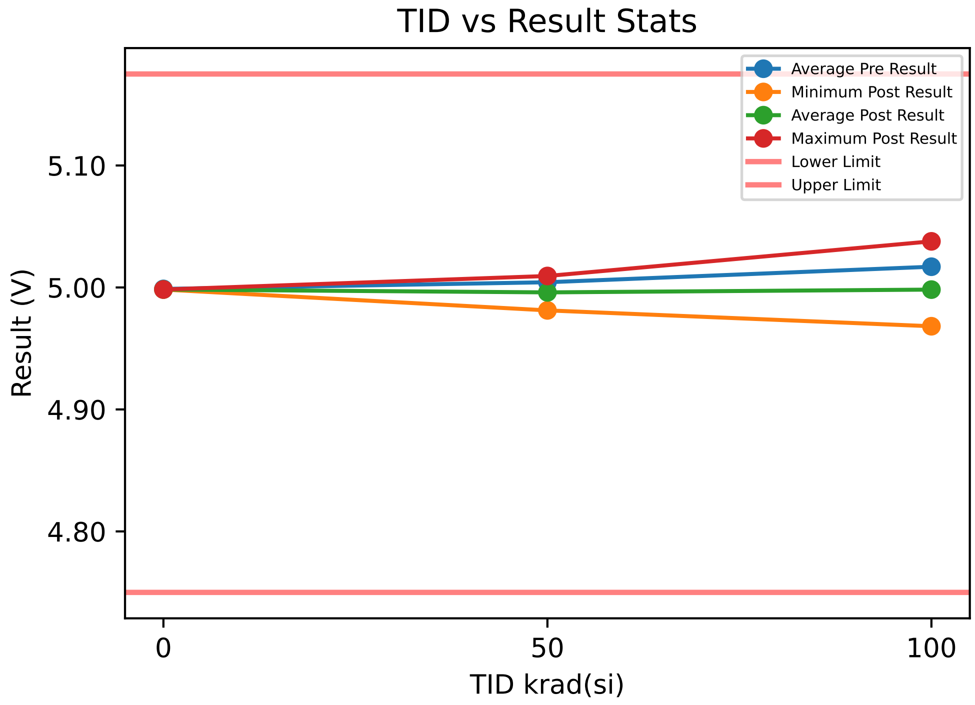
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

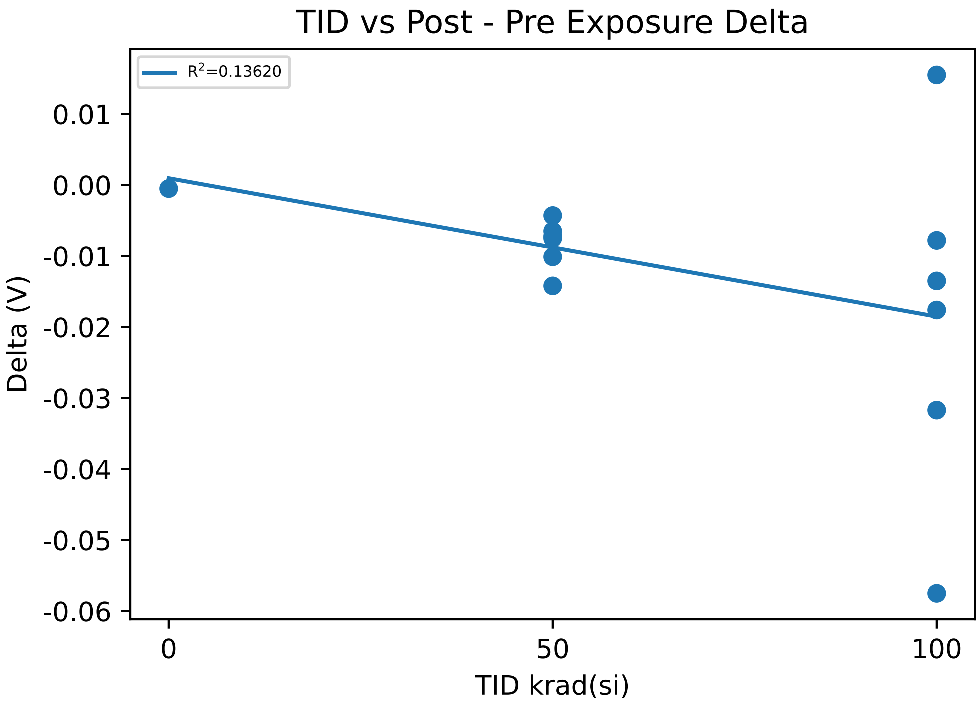
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0128	5.0119	-0.0009
60	50	Biased	4.99	4.9954	0.0054
61	50	Biased	5.0174	5.018	0.0006
63	100	Biased	5.012	4.9733	-0.0387
64	100	Biased	4.9966	4.9912	-0.0054
65	100	Biased	5.0119	4.9753	-0.0366
66	50	Unbiased	4.9931	4.9929	-0.0002
67	50	Unbiased	4.9994	4.9979	-0.0015
68	50	Unbiased	5.026	5.0253	-0.0007
69	100	Unbiased	5.027	5.0187	-0.0083
70	100	Unbiased	5.0004	5.0042	0.0038
71	100	Unbiased	5.0147	4.9713	-0.0434
72	0	Control	5.0115	5.0144	0.0029

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0115	5.0115	5.0115		5.0144	5.0144	5.0144		0.0029	0.0029	0.0029	
50	4.99	5.0065	5.026	0.014429	4.9929	5.0069	5.0253	0.013387	-0.0015	0.00045	0.0054	0.0025257
100	4.9966	5.0104	5.027	0.010856	4.9713	4.989	5.0187	0.019315	-0.0434	-0.021433	0.0038	0.020381

Device Test: 62.23 V_BP5H IIM 5MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

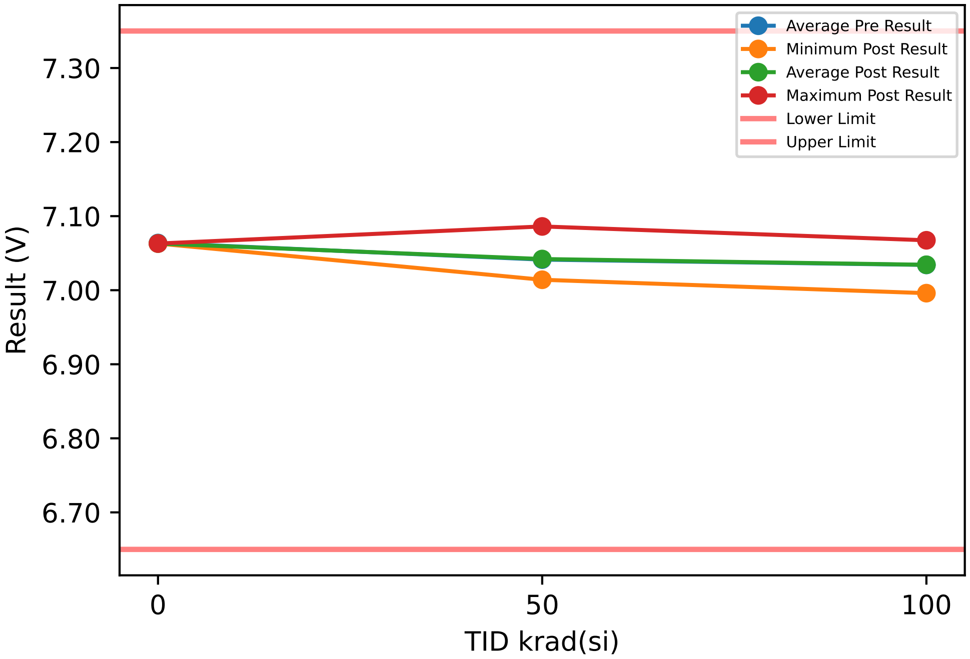
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0086	5.0021	-0.0065
60	50	Biased	4.9959	4.9884	-0.0075
61	50	Biased	5.0087	5.0044	-0.0043
63	100	Biased	5.0044	4.9868	-0.0176
64	100	Biased	5.0261	4.9944	-0.0317
65	100	Biased	5.0266	5.0188	-0.0078
66	50	Unbiased	4.9913	4.9812	-0.0101
67	50	Unbiased	4.9975	4.9903	-0.0072
68	50	Unbiased	5.0236	5.0094	-0.0142
69	100	Unbiased	5.0257	4.9682	-0.0575
70	100	Unbiased	4.9969	4.9834	-0.0135
71	100	Unbiased	5.0223	5.0378	0.0155
72	0	Control	4.9988	4.9983	-0.0005

Test Statistics (V)

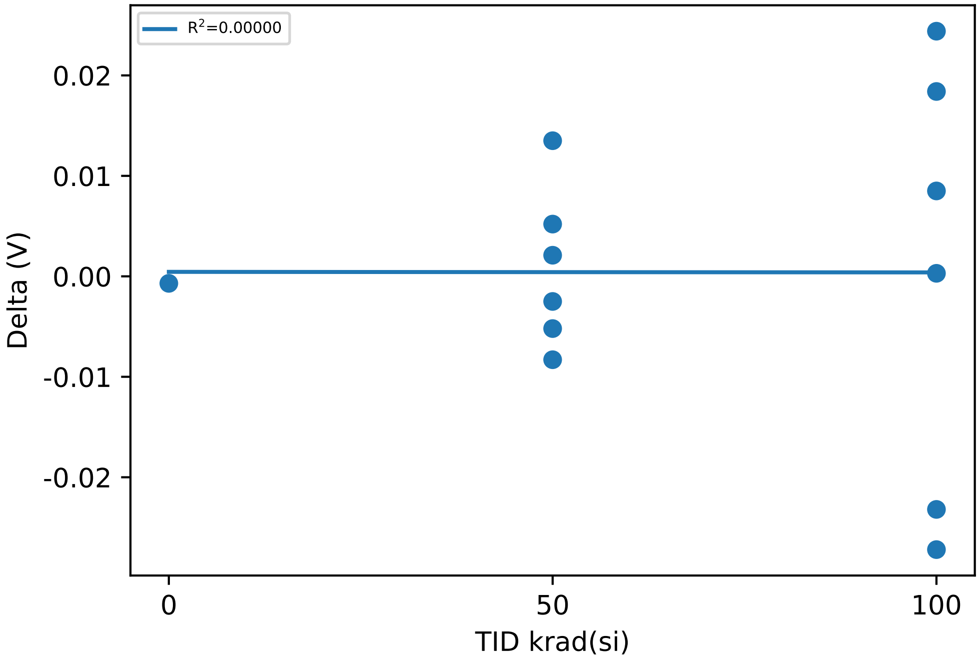
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9988	4.9988	4.9988		4.9983	4.9983	4.9983		-0.0005	-0.0005	-0.0005	
50	4.9913	5.0043	5.0236	0.011799	4.9812	4.996	5.0094	0.010923	-0.0142	-0.0083	-0.0043	0.0034392
100	4.9969	5.017	5.0266	0.012973	4.9682	4.9982	5.0378	0.025518	-0.0575	-0.018767	0.0155	0.024459

Device Test: 62.3 V_BP7L PWM 1MHz VIN_14V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



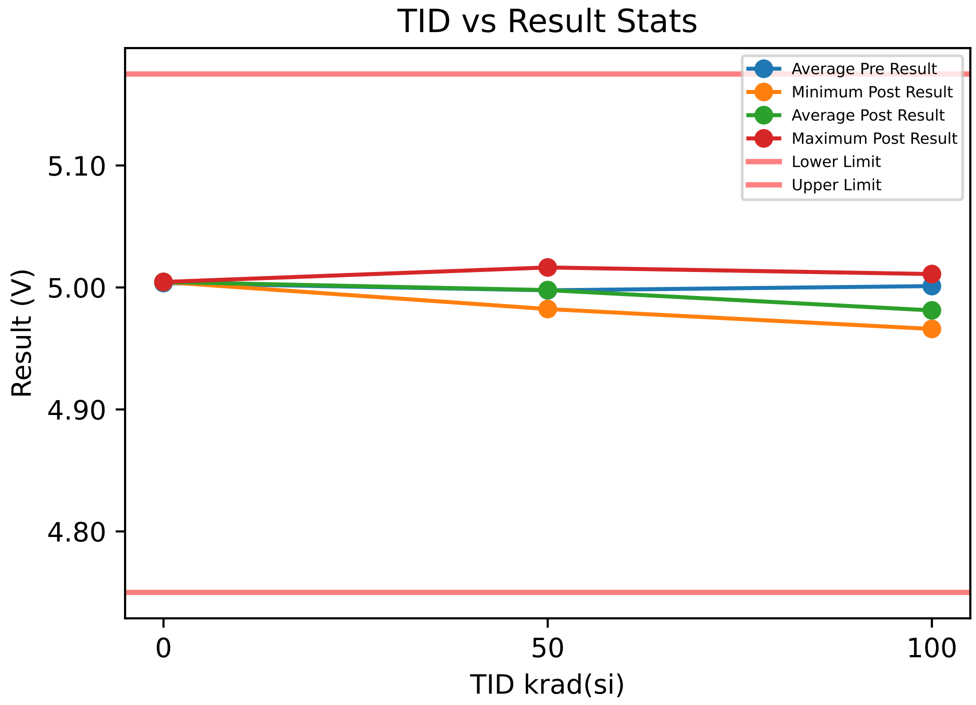
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

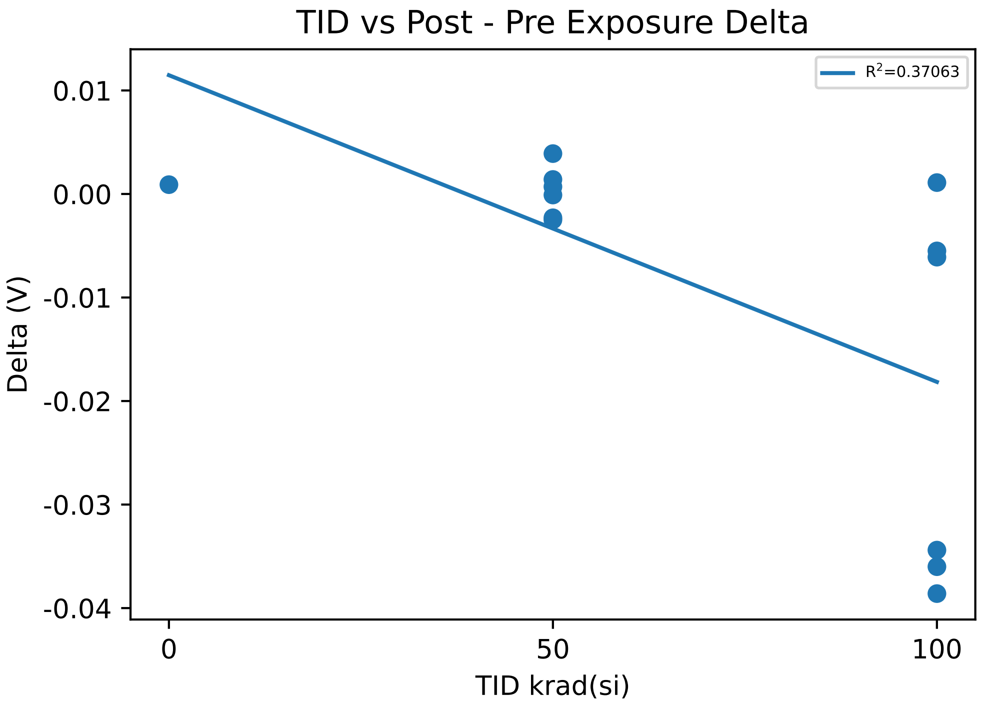
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0591	7.0539	-0.0052
60	50	Biased	7.0224	7.0141	-0.0083
61	50	Biased	7.04	7.0421	0.0021
63	100	Biased	7.0428	7.0513	0.0085
64	100	Biased	7.0382	7.015	-0.0232
65	100	Biased	7.0671	7.0674	0.0003
66	50	Unbiased	7.0249	7.0224	-0.0025
67	50	Unbiased	7.0205	7.034	0.0135
68	50	Unbiased	7.0809	7.0861	0.0052
69	100	Unbiased	7.0313	7.0497	0.0184
70	100	Unbiased	6.9716	6.996	0.0244
71	100	Unbiased	7.0538	7.0266	-0.0272
72	0	Control	7.0637	7.063	-0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0637	7.0637	7.0637		7.063	7.063	7.063		-0.0007	-0.0007	-0.0007	
50	7.0205	7.0413	7.0809	0.024271	7.0141	7.0421	7.0861	0.025741	-0.0083	0.0008	0.0135	0.0078999
100	6.9716	7.0341	7.0671	0.033117	6.996	7.0343	7.0674	0.026535	-0.0272	0.0002	0.0244	0.021373

Device Test: 62.4 V_BP5L PWM 1MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

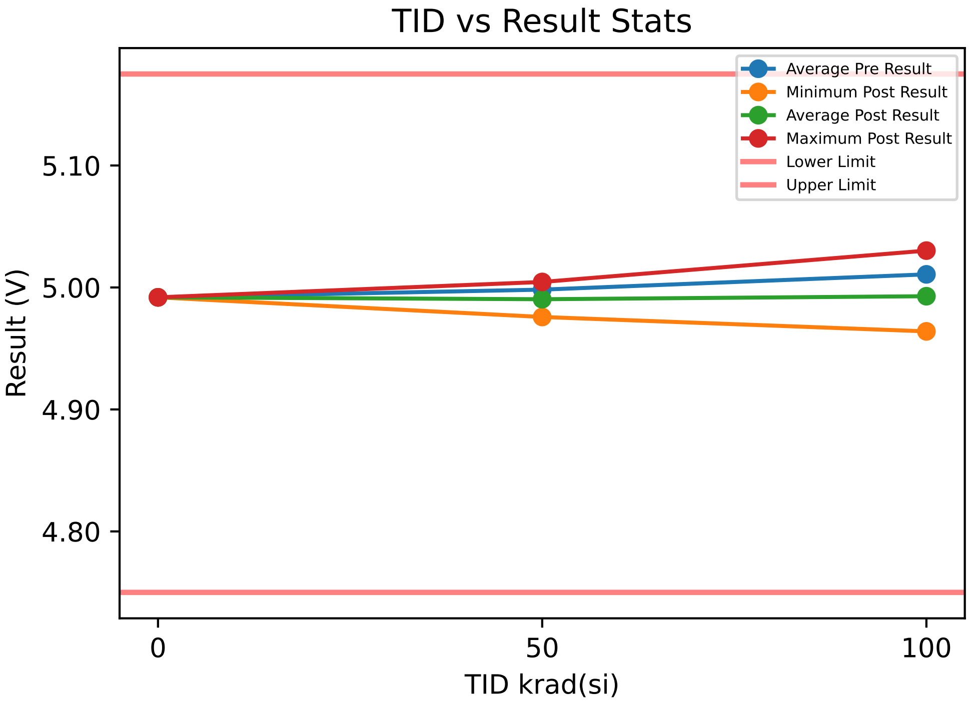
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

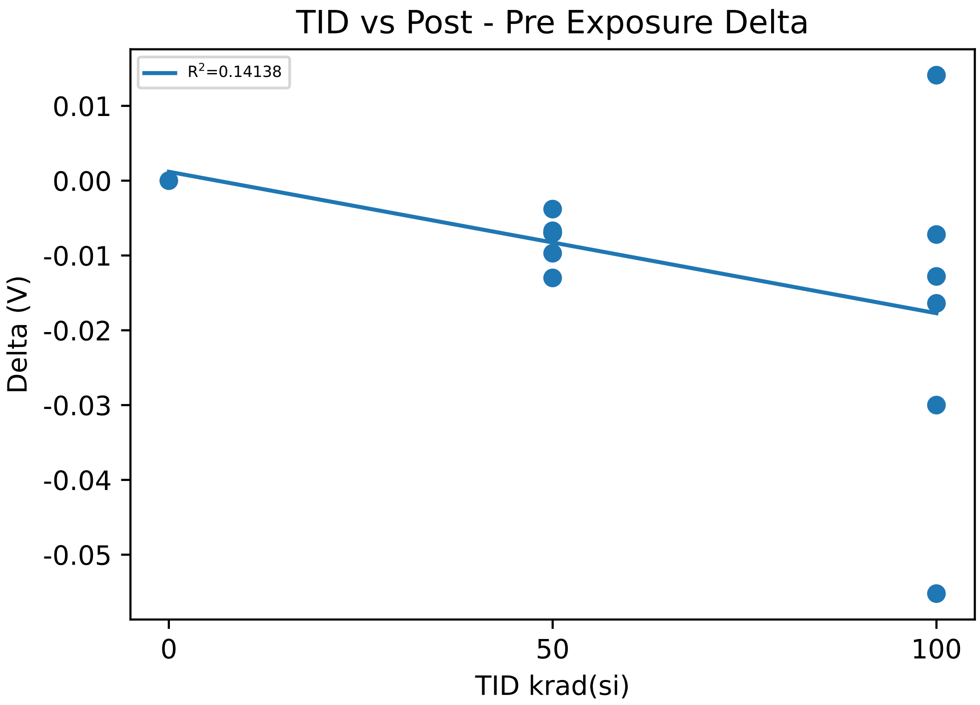
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0028	5.0027	-0.0001
60	50	Biased	4.9829	4.9868	0.0039
61	50	Biased	5.0077	5.0091	0.0014
63	100	Biased	5.0026	4.9666	-0.036
64	100	Biased	4.9897	4.9836	-0.0061
65	100	Biased	5.0009	4.9665	-0.0344
66	50	Unbiased	4.9848	4.9823	-0.0025
67	50	Unbiased	4.989	4.9897	0.0007
68	50	Unbiased	5.0187	5.0164	-0.0023
69	100	Unbiased	5.0165	5.011	-0.0055
70	100	Unbiased	4.9924	4.9935	0.0011
71	100	Unbiased	5.0046	4.966	-0.0386
72	0	Control	5.0036	5.0045	0.0009

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0036	5.0036	5.0036		5.0045	5.0045	5.0045		0.0009	0.0009	0.0009	
50	4.9829	4.9977	5.0187	0.01434	4.9823	4.9978	5.0164	0.013598	-0.0025	0.00018333	0.0039	0.0024087
100	4.9897	5.0011	5.0165	0.009564	4.966	4.9812	5.011	0.018468	-0.0386	-0.019917	0.0011	0.01821

Device Test: 62.5 V_BP5H PWM 1MHz VIN_14V





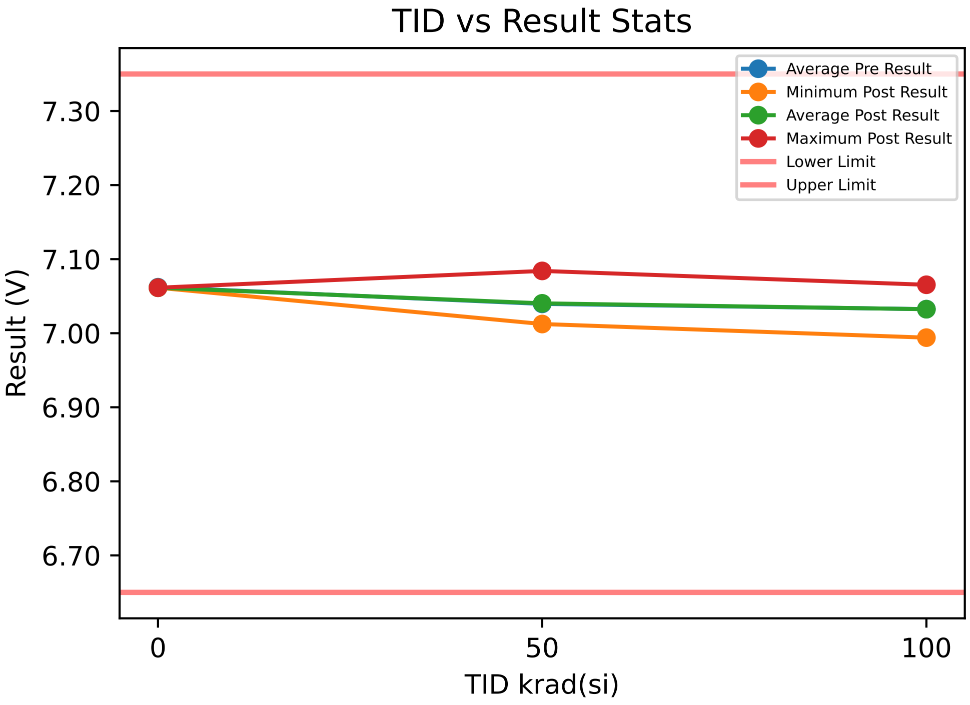
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0028	4.9961	-0.0067
60	50	Biased	4.9898	4.9828	-0.007
61	50	Biased	5.0025	4.9987	-0.0038
63	100	Biased	4.9981	4.9817	-0.0164
64	100	Biased	5.0201	4.9901	-0.03
65	100	Biased	5.0204	5.0132	-0.0072
66	50	Unbiased	4.9855	4.9758	-0.0097
67	50	Unbiased	4.9912	4.9842	-0.007
68	50	Unbiased	5.0175	5.0045	-0.013
69	100	Unbiased	5.0192	4.964	-0.0552
70	100	Unbiased	4.9905	4.9777	-0.0128
71	100	Unbiased	5.0161	5.0302	0.0141
72	0	Control	4.9919	4.9919	0

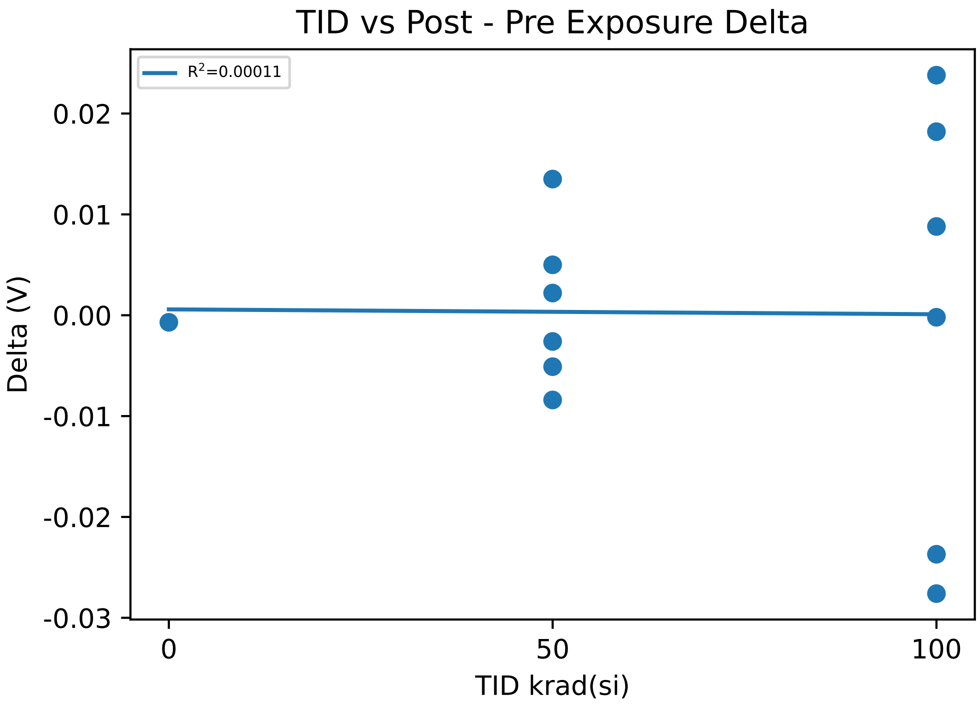
Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9919	4.9919	4.9919		4.9919	4.9919	4.9919		0	0	0	
50	4.9855	4.9982	5.0175	0.011773	4.9758	4.9904	5.0045	0.011041	-0.013	-0.0078667	-0.0038	0.0031341
100	4.9905	5.0107	5.0204	0.013043	4.964	4.9928	5.0302	0.024507	-0.0552	-0.017917	0.0141	0.023257

Device Test: 62.6 V_BP7L PWM 2MHz VIN_14V



TID vs Result Stats



TID vs Post - Pre Exposure Delta

Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

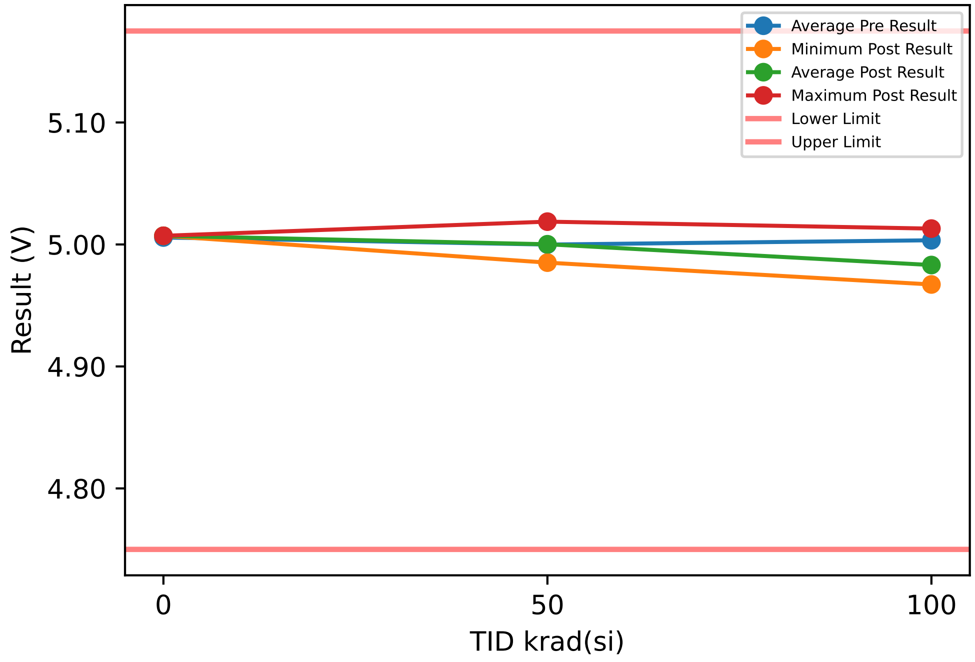
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0572	7.0521	-0.0051
60	50	Biased	7.0208	7.0124	-0.0084
61	50	Biased	7.0383	7.0405	0.0022
63	100	Biased	7.041	7.0498	0.0088
64	100	Biased	7.0368	7.0131	-0.0237
65	100	Biased	7.0656	7.0654	-0.0002
66	50	Unbiased	7.0233	7.0207	-0.0026
67	50	Unbiased	7.0187	7.0322	0.0135
68	50	Unbiased	7.0791	7.0841	0.005
69	100	Unbiased	7.0295	7.0477	0.0182
70	100	Unbiased	6.9702	6.994	0.0238
71	100	Unbiased	7.0519	7.0243	-0.0276
72	0	Control	7.0621	7.0614	-0.0007

Test Statistics (V)

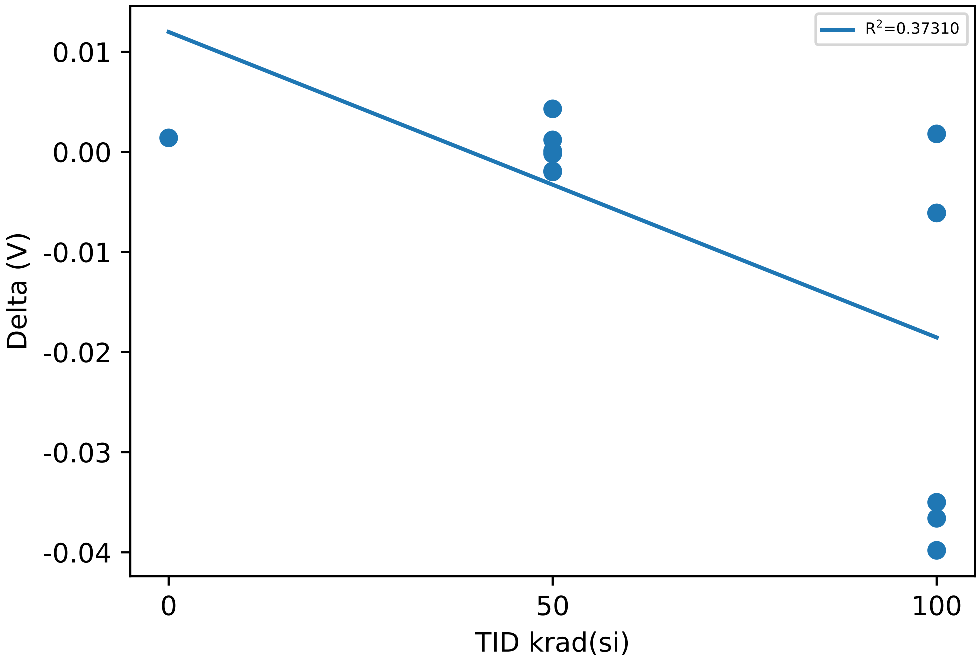
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0621	7.0621	7.0621		7.0614	7.0614	7.0614		-0.0007	-0.0007	-0.0007	
50	7.0187	7.0396	7.0791	0.024198	7.0124	7.0403	7.0841	0.025635	-0.0084	0.00076667	0.0135	0.007898
100	6.9702	7.0325	7.0656	0.033024	6.994	7.0324	7.0654	0.026603	-0.0276	-0.00011667	0.0238	0.021441

Device Test: 62.7 V_BP5L PWM 2MHz VIN_14V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



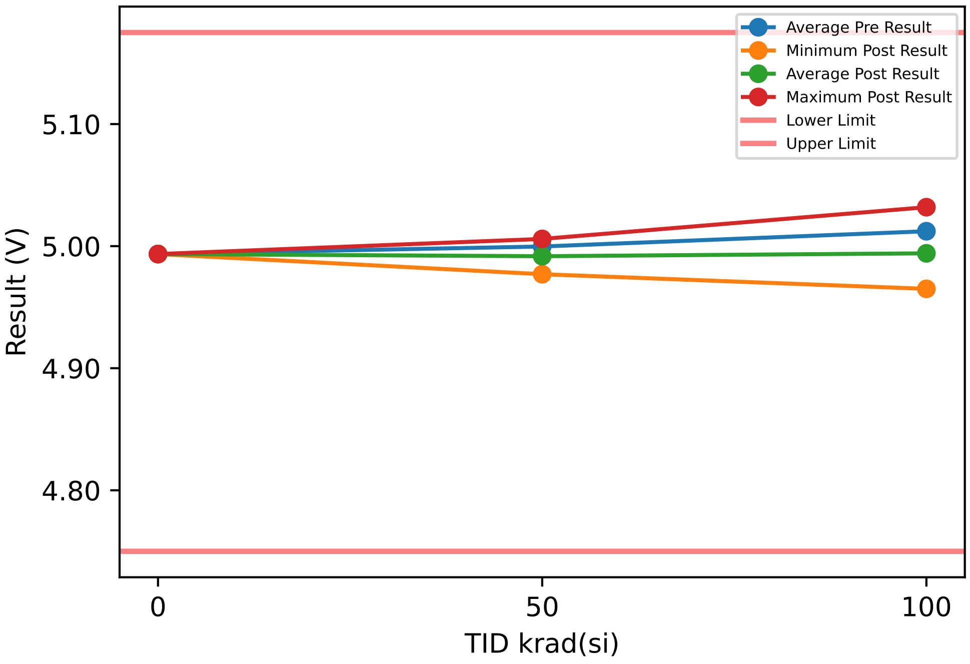
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

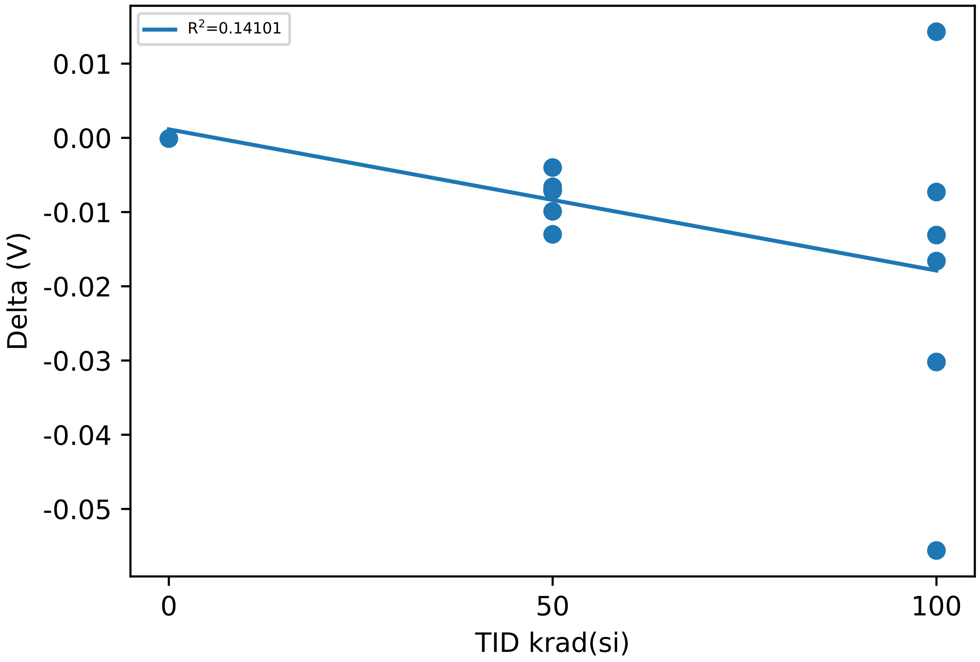
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0053	5.0051	-0.0002
60	50	Biased	4.9847	4.989	0.0043
61	50	Biased	5.0102	5.0114	0.0012
63	100	Biased	5.0049	4.9683	-0.0366
64	100	Biased	4.9915	4.9854	-0.0061
65	100	Biased	5.0037	4.9687	-0.035
66	50	Unbiased	4.987	4.9851	-0.0019
67	50	Unbiased	4.9916	4.9917	0.0001
68	50	Unbiased	5.0207	5.0187	-0.002
69	100	Unbiased	5.0191	5.013	-0.0061
70	100	Unbiased	4.9944	4.9962	0.0018
71	100	Unbiased	5.007	4.9672	-0.0398
72	0	Control	5.0057	5.0071	0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0057	5.0057	5.0057		5.0071	5.0071	5.0071		0.0014	0.0014	0.0014	
50	4.9847	4.9999	5.0207	0.014382	4.9851	5.0002	5.0187	0.013545	-0.002	0.00025	0.0043	0.002333
100	4.9915	5.0034	5.0191	0.0098427	4.9672	4.9831	5.013	0.018709	-0.0398	-0.0203	0.0018	0.018728

Device Test: 62.8 V_BP5H PWM 2MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

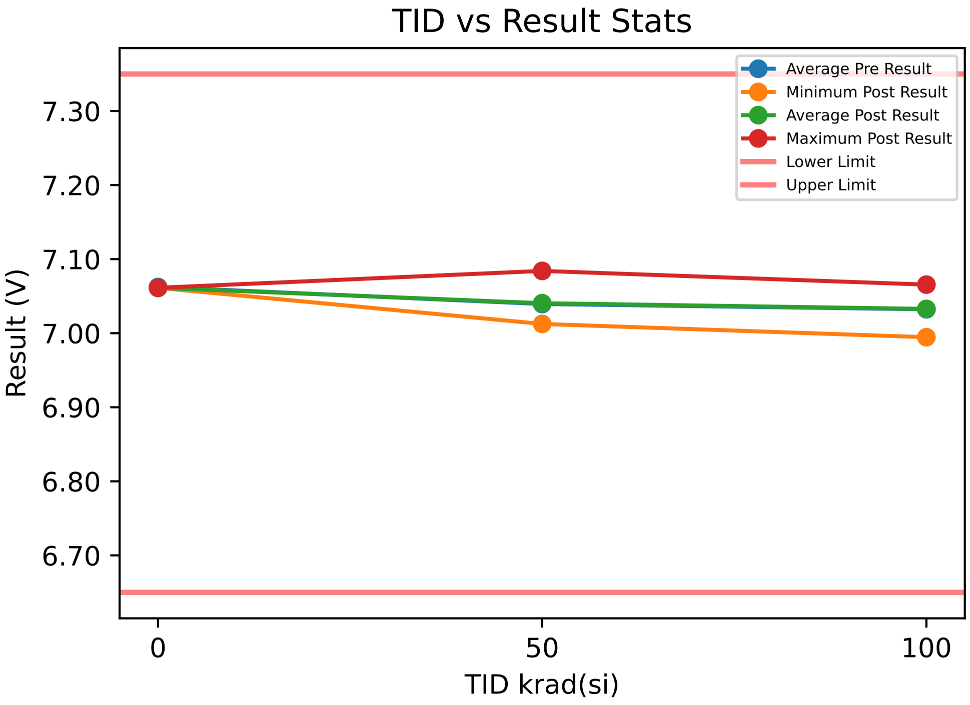
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

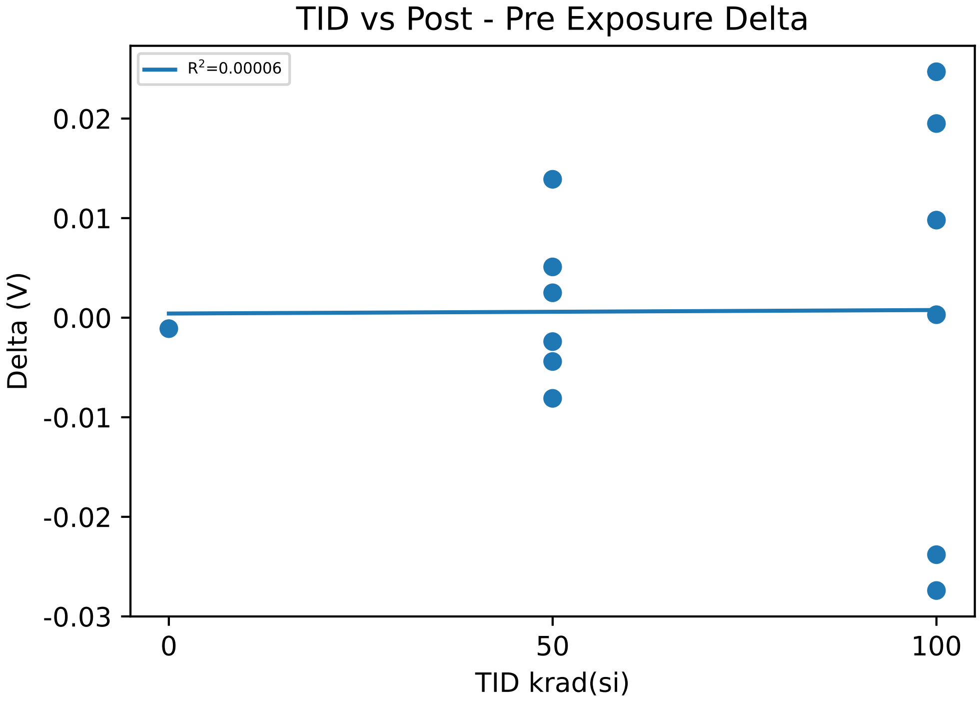
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0042	4.9976	-0.0066
60	50	Biased	4.9913	4.9842	-0.0071
61	50	Biased	5.0042	5.0002	-0.004
63	100	Biased	4.9996	4.983	-0.0166
64	100	Biased	5.0215	4.9913	-0.0302
65	100	Biased	5.0218	5.0145	-0.0073
66	50	Unbiased	4.9869	4.977	-0.0099
67	50	Unbiased	4.9927	4.9856	-0.0071
68	50	Unbiased	5.0189	5.0059	-0.013
69	100	Unbiased	5.0206	4.965	-0.0556
70	100	Unbiased	4.9921	4.979	-0.0131
71	100	Unbiased	5.0176	5.0319	0.0143
72	0	Control	4.9936	4.9935	-0.0001

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9936	4.9936	4.9936		4.9935	4.9935	4.9935		-0.0001	-0.0001	-0.0001	
50	4.9869	4.9997	5.0189	0.011769	4.977	4.9918	5.0059	0.01112	-0.013	-0.00795	-0.004	0.003104
100	4.9921	5.0122	5.0218	0.01297	4.965	4.9941	5.0319	0.024702	-0.0556	-0.018083	0.0143	0.023436

Device Test: 62.9 V_BP7L PWM 5MHz VIN_14V





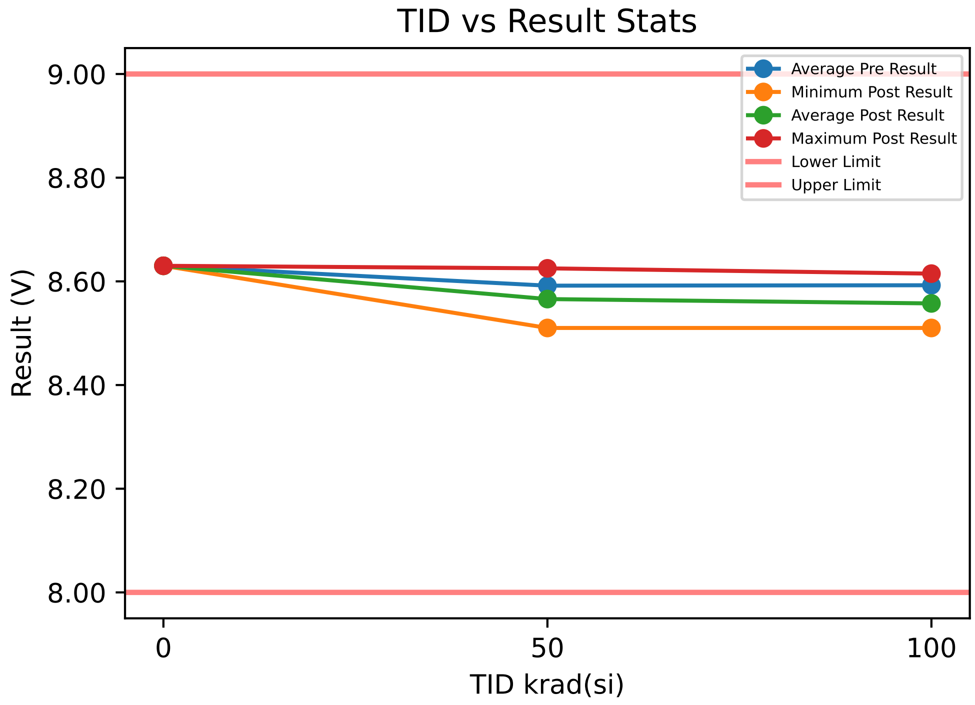
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

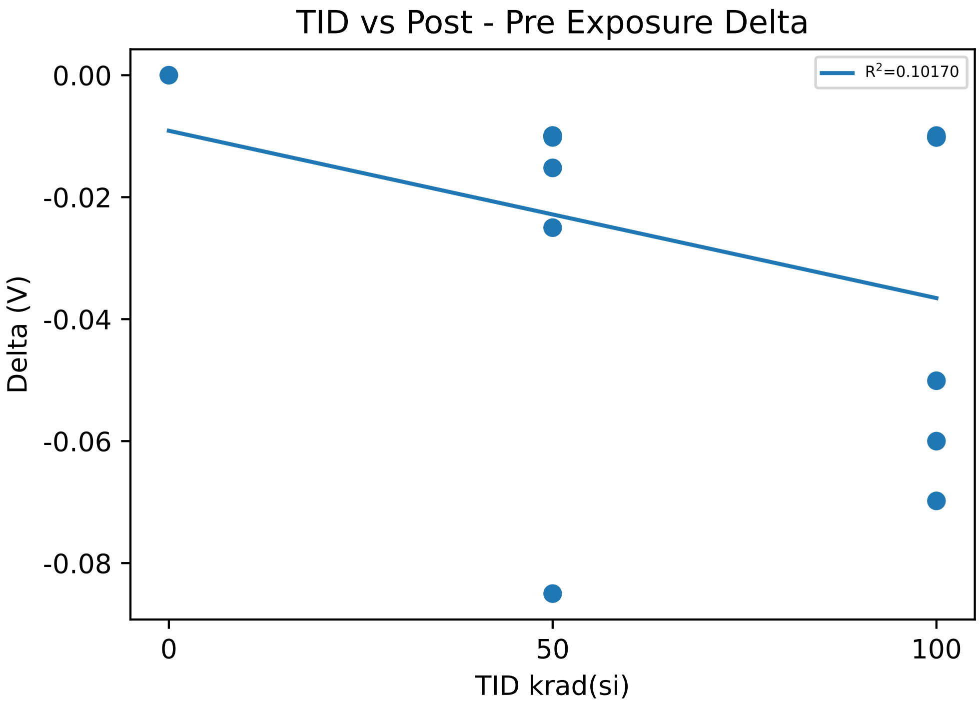
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.057	7.0526	-0.0044
60	50	Biased	7.0206	7.0125	-0.0081
61	50	Biased	7.0381	7.0406	0.0025
63	100	Biased	7.0405	7.0503	0.0098
64	100	Biased	7.0371	7.0133	-0.0238
65	100	Biased	7.0653	7.0656	0.0003
66	50	Unbiased	7.0231	7.0207	-0.0024
67	50	Unbiased	7.0187	7.0326	0.0139
68	50	Unbiased	7.079	7.0841	0.0051
69	100	Unbiased	7.0291	7.0486	0.0195
70	100	Unbiased	6.9699	6.9946	0.0247
71	100	Unbiased	7.0519	7.0245	-0.0274
72	0	Control	7.0624	7.0613	-0.0011

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0624	7.0624	7.0624		7.0613	7.0613	7.0613		-0.0011	-0.0011	-0.0011	
50	7.0187	7.0394	7.079	0.024196	7.0125	7.0405	7.0841	0.025635	-0.0081	0.0011	0.0139	0.0078605
100	6.9699	7.0323	7.0653	0.033068	6.9946	7.0328	7.0656	0.026609	-0.0274	0.00051667	0.0247	0.021918

Device Test: 70.0 UVLO VIN Rise Thresh


TID vs Result Stats


TID vs Post - Pre Exposure Delta

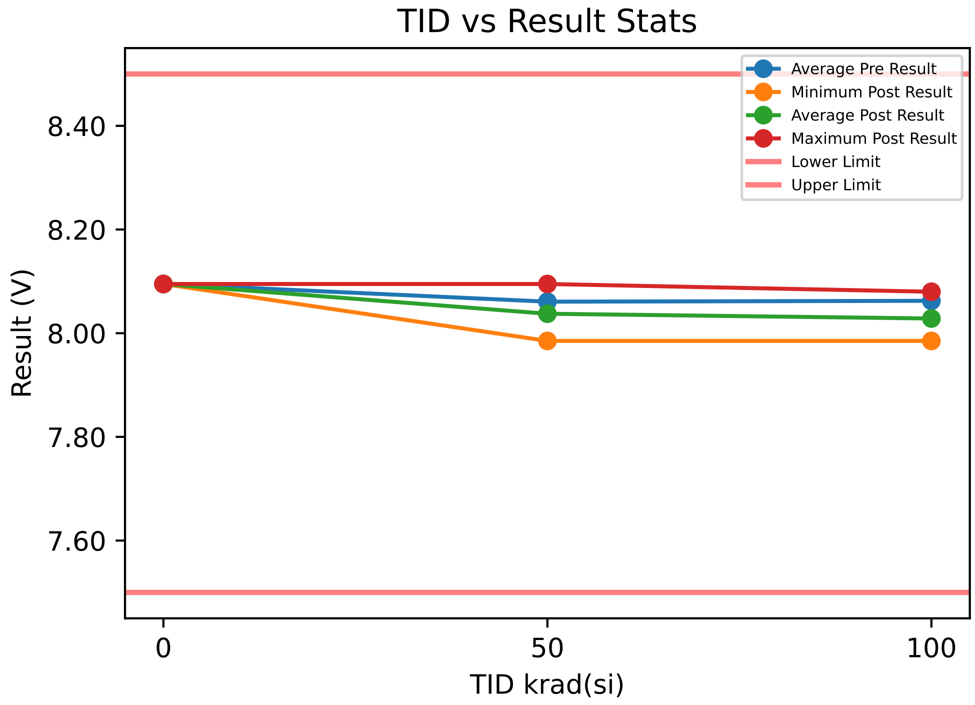
Test Results (Lower Limit = 8.0, Upper Limit = 9.0 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	8.5951	8.5799	-0.0152
60	50	Biased	8.5951	8.5101	-0.085
61	50	Biased	8.545	8.52	-0.025
63	100	Biased	8.63	8.5799	-0.0501
64	100	Biased	8.5849	8.5249	-0.06
65	100	Biased	8.5799	8.5101	-0.0698
66	50	Unbiased	8.635	8.6251	-0.0099
67	50	Unbiased	8.6149	8.605	-0.0099
68	50	Unbiased	8.5651	8.5549	-0.0102
69	100	Unbiased	8.6251	8.6149	-0.0102
70	100	Unbiased	8.6	8.5901	-0.0099
71	100	Unbiased	8.5351	8.5249	-0.0102
72	0	Control	8.63	8.63	0

Test Statistics (V)

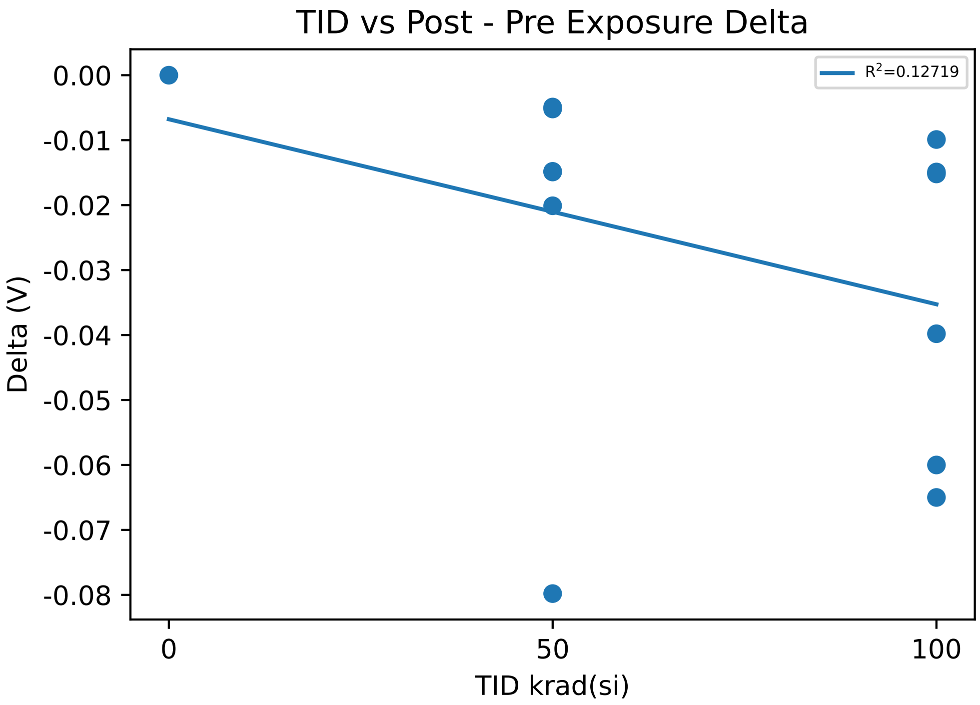
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.63	8.63	8.63		8.63	8.63	8.63		0	0	0	
50	8.545	8.5917	8.635	0.032633	8.5101	8.5658	8.6251	0.04598	-0.085	-0.025867	-0.0099	0.029552
100	8.5351	8.5925	8.63	0.034746	8.5101	8.5575	8.6149	0.042969	-0.0698	-0.035033	-0.0099	0.028015

Device Test: 70.1 UVLO VIN Fall Thresh



Test Results (Lower Limit = 7.5, Upper Limit = 8.5 (V))

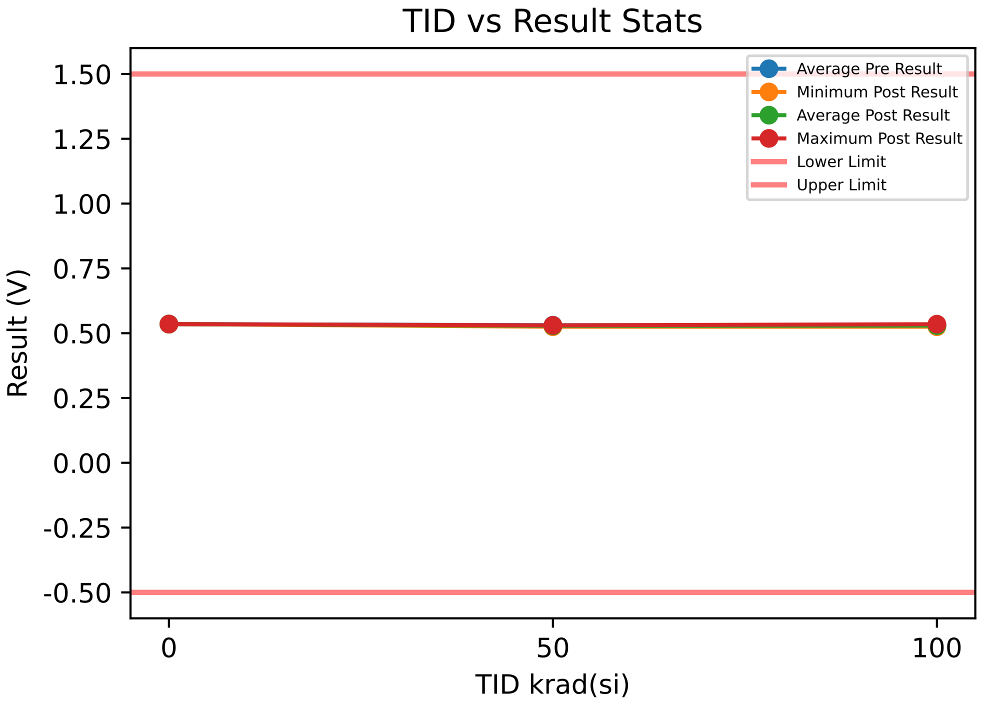
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	8.0649	8.0501	-0.0148
60	50	Biased	8.0649	7.9851	-0.0798
61	50	Biased	8.0151	7.995	-0.0201
63	100	Biased	8.0899	8.0501	-0.0398
64	100	Biased	8.055	7.995	-0.06
65	100	Biased	8.0501	7.9851	-0.065
66	50	Unbiased	8.1001	8.0949	-0.0052
67	50	Unbiased	8.08	8.0751	-0.0049
68	50	Unbiased	8.0399	8.025	-0.0149
69	100	Unbiased	8.0949	8.08	-0.0149
70	100	Unbiased	8.0751	8.0599	-0.0152
71	100	Unbiased	8.0099	8	-0.0099
72	0	Control	8.0949	8.0949	0

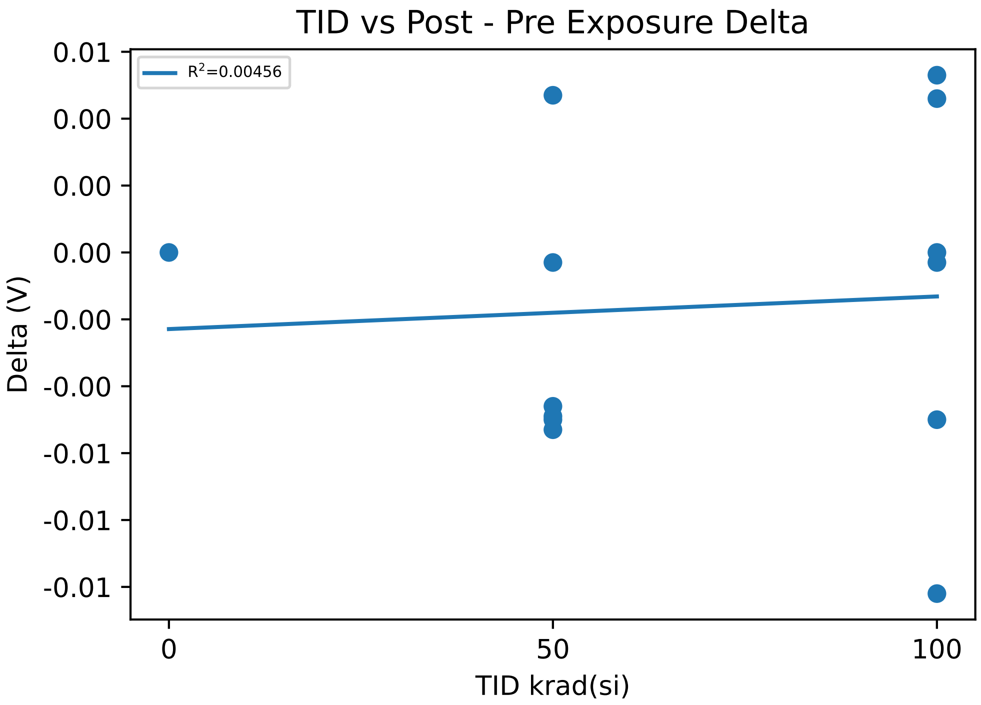


Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0949	8.0949	8.0949		8.0949	8.0949	8.0949		0	0	0	
50	8.0151	8.0608	8.1001	0.029907	7.9851	8.0375	8.0949	0.043762	-0.0798	-0.023283	-0.0049	0.028325
100	8.0099	8.0625	8.0949	0.03142	7.9851	8.0284	8.08	0.039806	-0.065	-0.034133	-0.0099	0.02437

Device Test: 70.2 UVLO VIN Thresh Hysteresis





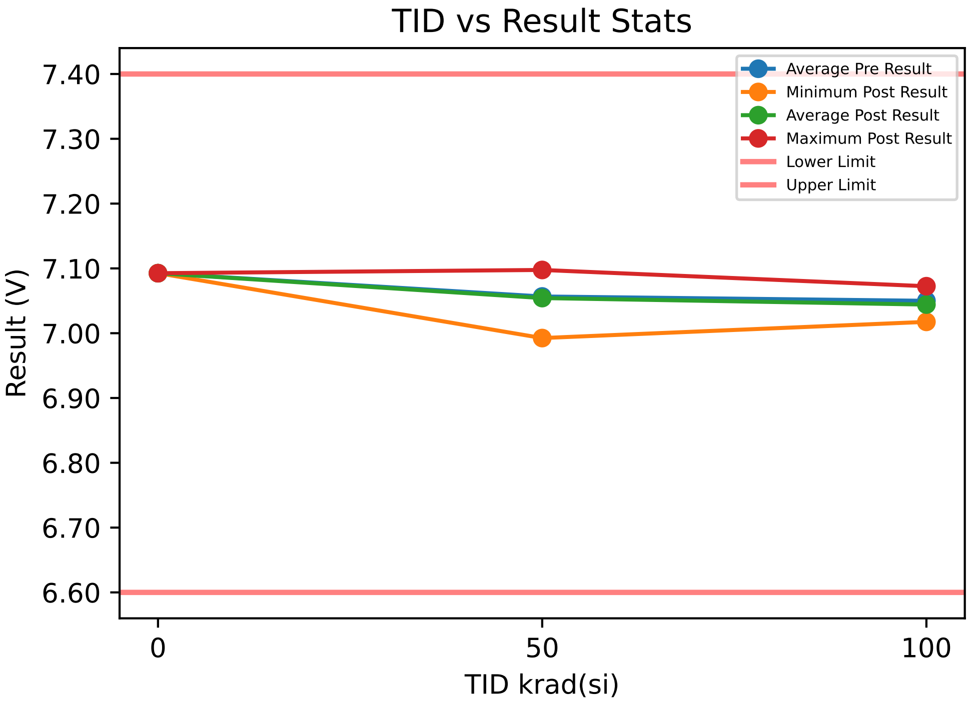
Test Results (Lower Limit = -0.5, Upper Limit = 1.5 (V))

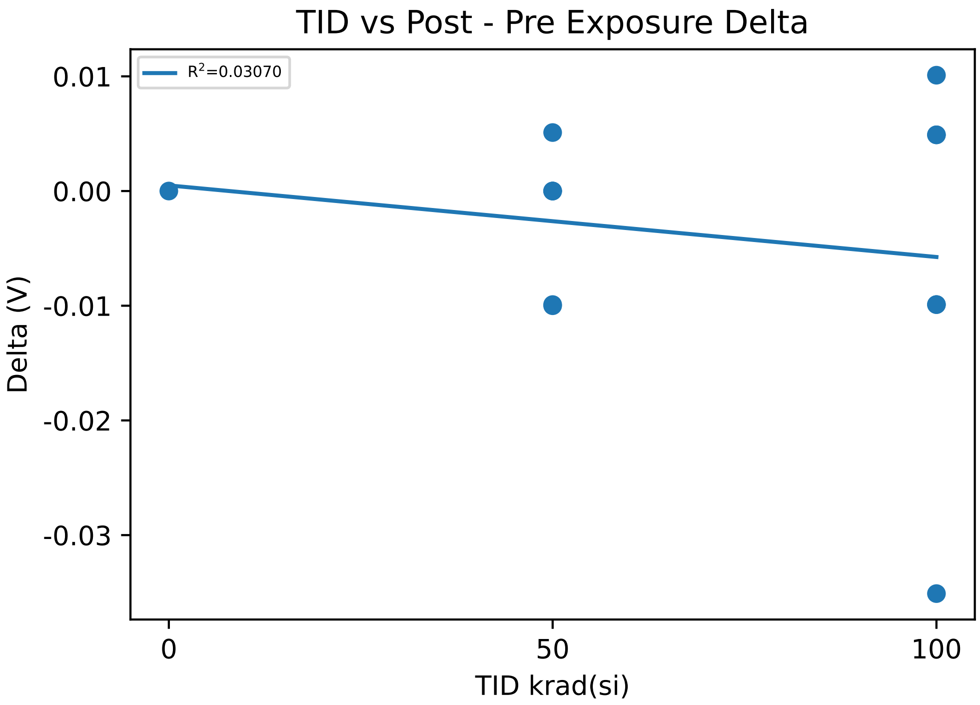
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.5302	0.5299	-0.0003
60	50	Biased	0.5302	0.5249	-0.0053
61	50	Biased	0.5299	0.5249	-0.005
63	100	Biased	0.5401	0.5299	-0.0102
64	100	Biased	0.5299	0.5299	0
65	100	Biased	0.5299	0.5249	-0.005
66	50	Unbiased	0.5348	0.5302	-0.0046
67	50	Unbiased	0.5348	0.5299	-0.0049
68	50	Unbiased	0.5252	0.5299	0.0047
69	100	Unbiased	0.5302	0.5348	0.0046
70	100	Unbiased	0.5249	0.5302	0.0053
71	100	Unbiased	0.5252	0.5249	-0.0003
72	0	Control	0.5351	0.5351	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5351	0.5351	0.5351		0.5351	0.5351	0.5351		0	0	0	
50	0.5252	0.53085	0.5348	0.0036021	0.5249	0.52828	0.5302	0.0026233	-0.0053	-0.0025667	0.0047	0.0040228
100	0.5249	0.53003	0.5401	0.0054975	0.5249	0.5291	0.5348	0.0037486	-0.0102	-0.00093333	0.0053	0.0058848

Device Test: 75.0 UVLO BOOT Rise Thresh





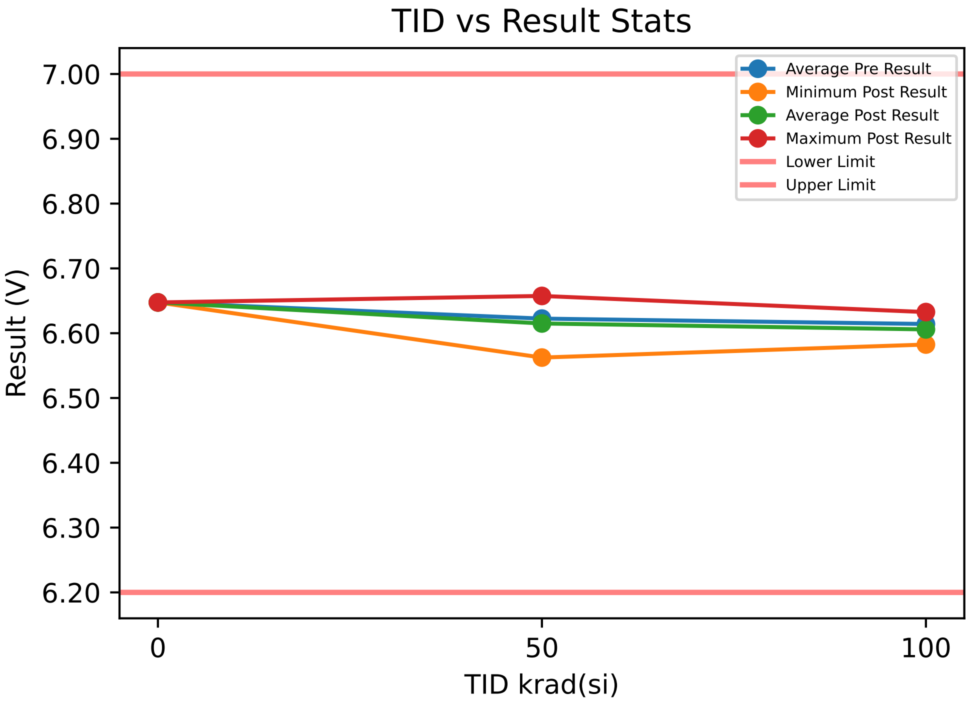
Test Results (Lower Limit = 6.6, Upper Limit = 7.4 (V))

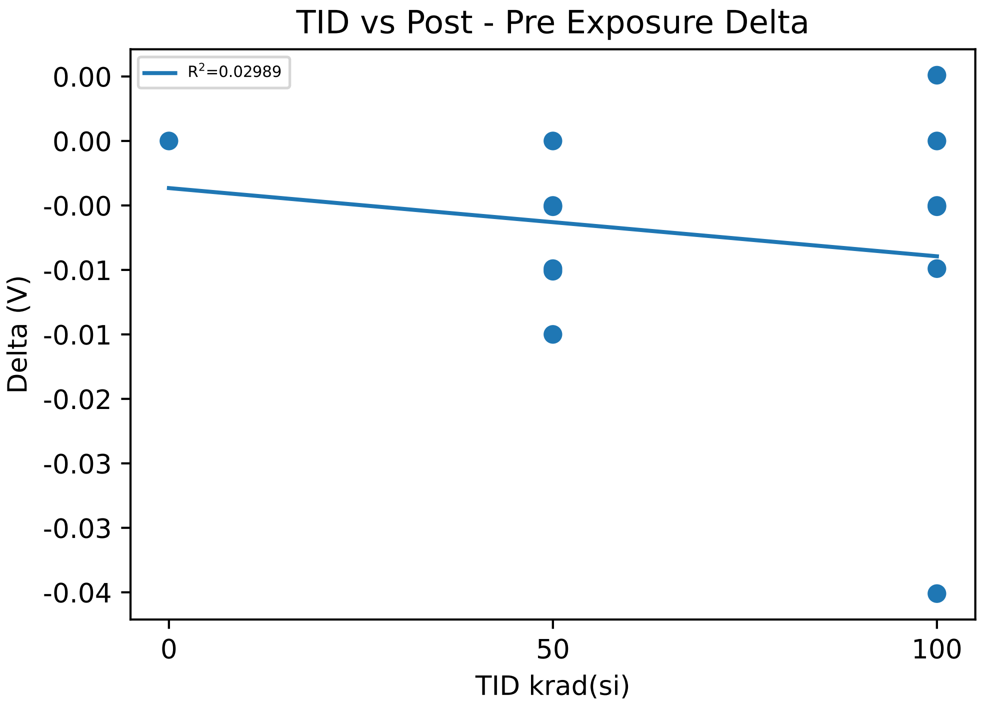
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	7.0976	7.0976	0
60	50	Biased	7.0676	7.0676	0
61	50	Biased	7.0824	7.0875	0.0051
63	100	Biased	7.0224	7.0325	0.0101
64	100	Biased	7.0475	7.0376	-0.0099
65	100	Biased	7.0274	7.0175	-0.0099
66	50	Unbiased	7.0025	6.9925	-0.01
67	50	Unbiased	7.0425	7.0425	0
68	50	Unbiased	7.0475	7.0376	-0.0099
69	100	Unbiased	7.0976	7.0625	-0.0351
70	100	Unbiased	7.0376	7.0425	0.0049
71	100	Unbiased	7.0676	7.0725	0.0049
72	0	Control	7.0926	7.0926	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0926	7.0926	7.0926		7.0926	7.0926	7.0926		0	0	0	
50	7.0025	7.0567	7.0976	0.033693	6.9925	7.0542	7.0976	0.038448	-0.01	-0.0024667	0.0051	0.0061239
100	7.0224	7.05	7.0976	0.028313	7.0175	7.0442	7.0725	0.020159	-0.0351	-0.0058333	0.0101	0.016576

Device Test: 75.1 UVLO BOOT Fall Thresh





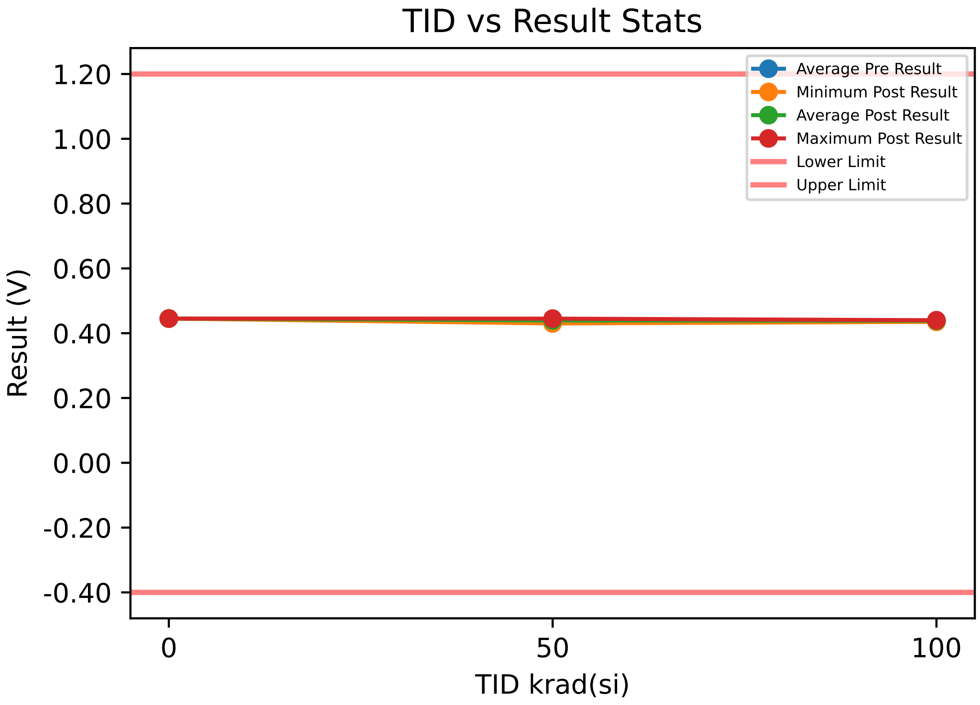
Test Results (Lower Limit = 6.2, Upper Limit = 7.0 (V))

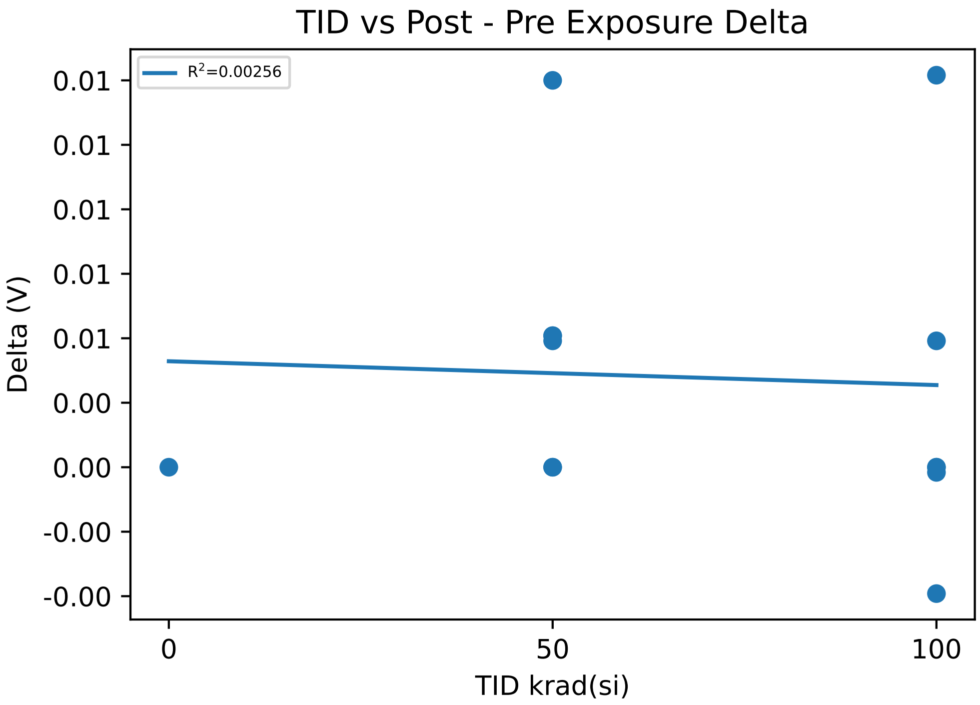
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.6626	6.6575	-0.0051
60	50	Biased	6.6275	6.6275	0
61	50	Biased	6.6524	6.6425	-0.0099
63	100	Biased	6.5975	6.5924	-0.0051
64	100	Biased	6.6076	6.6026	-0.005
65	100	Biased	6.5924	6.5825	-0.0099
66	50	Unbiased	6.5725	6.5624	-0.0101
67	50	Unbiased	6.6076	6.6026	-0.005
68	50	Unbiased	6.6125	6.5975	-0.015
69	100	Unbiased	6.6575	6.6224	-0.0351
70	100	Unbiased	6.5975	6.6026	0.0051
71	100	Unbiased	6.6326	6.6326	0
72	0	Control	6.6475	6.6475	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.6475	6.6475	6.6475		6.6475	6.6475	6.6475		0	0	0	
50	6.5725	6.6225	6.6626	0.032708	6.5624	6.615	6.6575	0.034483	-0.015	-0.0075167	0	0.005235
100	6.5924	6.6142	6.6575	0.025652	6.5825	6.6059	6.6326	0.018637	-0.0351	-0.0083333	0.0051	0.014074

Device Test: 75.2 UVLO BOOT Thresh Hysteresis


TID vs Result Stats


TID vs Post - Pre Exposure Delta

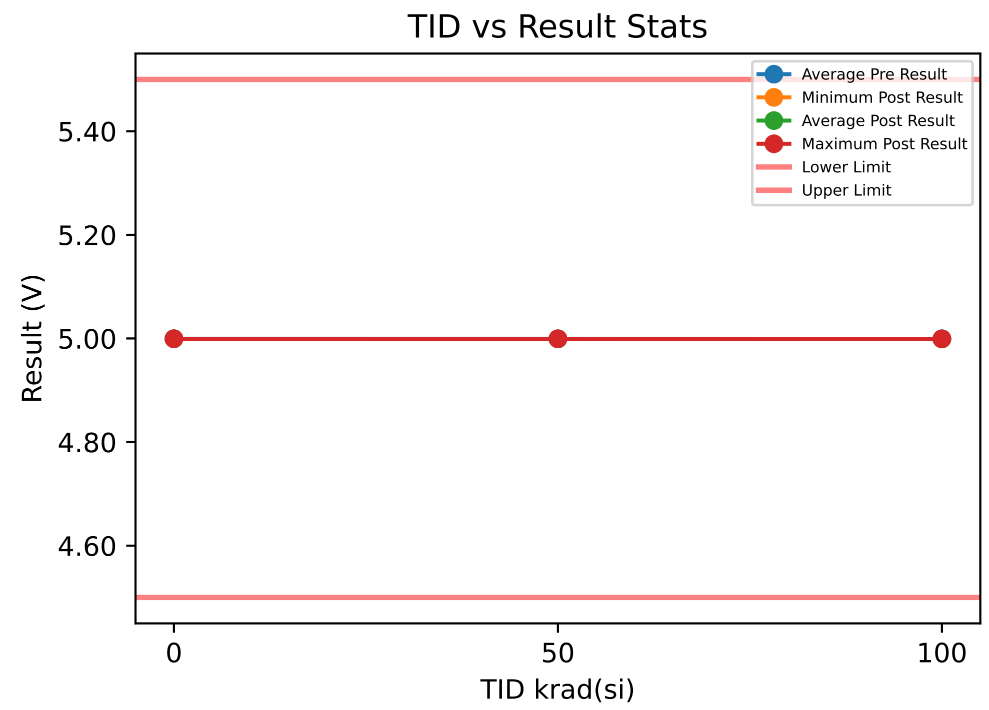
Test Results (Lower Limit = -0.4, Upper Limit = 1.2 (V))

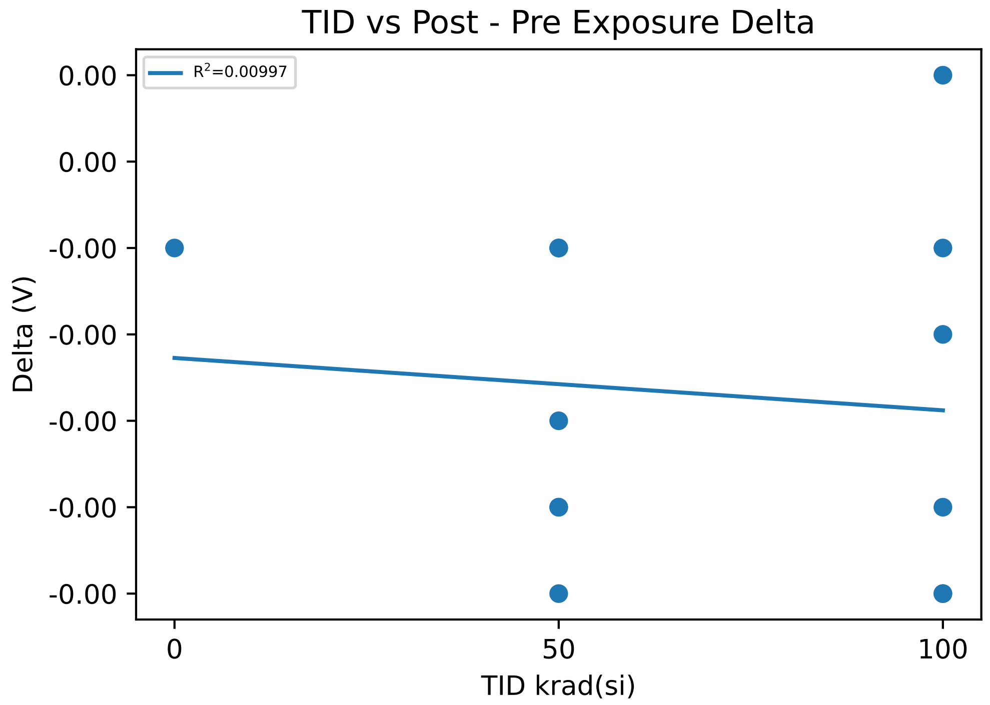
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.435	0.4401	0.0051
60	50	Biased	0.4401	0.4401	0
61	50	Biased	0.43	0.445	0.015
63	100	Biased	0.4249	0.4401	0.0152
64	100	Biased	0.4399	0.435	-0.0049
65	100	Biased	0.435	0.435	0
66	50	Unbiased	0.43	0.43	0
67	50	Unbiased	0.435	0.4399	0.0049
68	50	Unbiased	0.435	0.4401	0.0051
69	100	Unbiased	0.4401	0.4401	0
70	100	Unbiased	0.4401	0.4399	-0.0002
71	100	Unbiased	0.435	0.4399	0.0049
72	0	Control	0.4452	0.4452	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.4452	0.4452	0.4452		0.4452	0.4452	0.4452		0	0	0	
50	0.43	0.43418	0.4401	0.003795	0.43	0.4392	0.445	0.0049234	0	0.0050167	0.015	0.0054777
100	0.4249	0.43583	0.4401	0.005897	0.435	0.43833	0.4401	0.0025835	-0.0049	0.0025	0.0152	0.0069513

Device Test: 80.0 TM1 - LMUX V VIN_10V





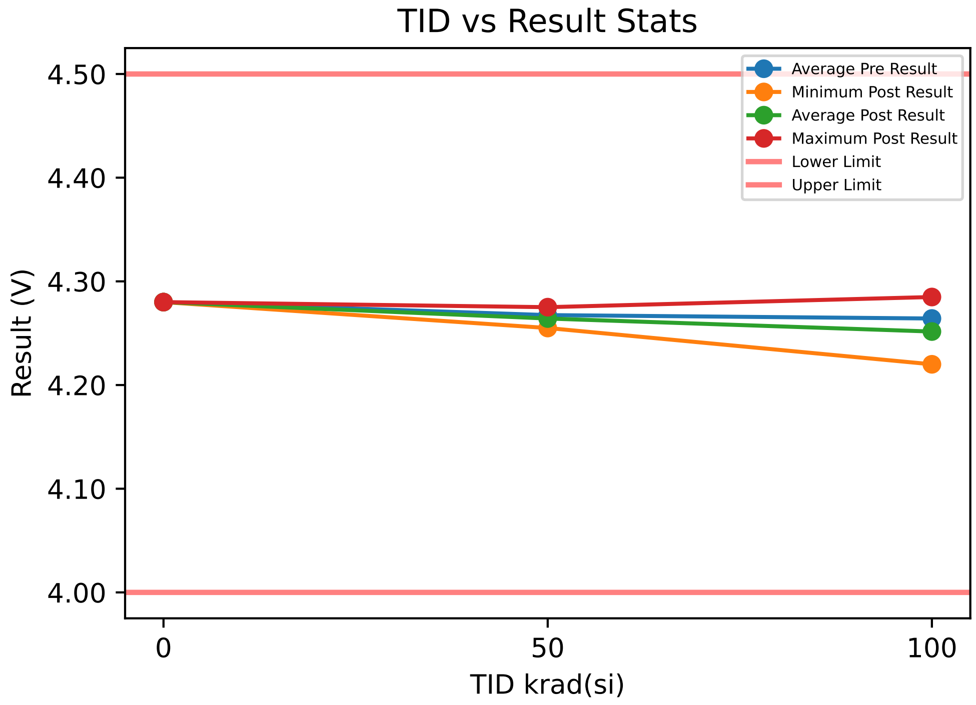
Test Results (Lower Limit = 4.5, Upper Limit = 5.5 (V))

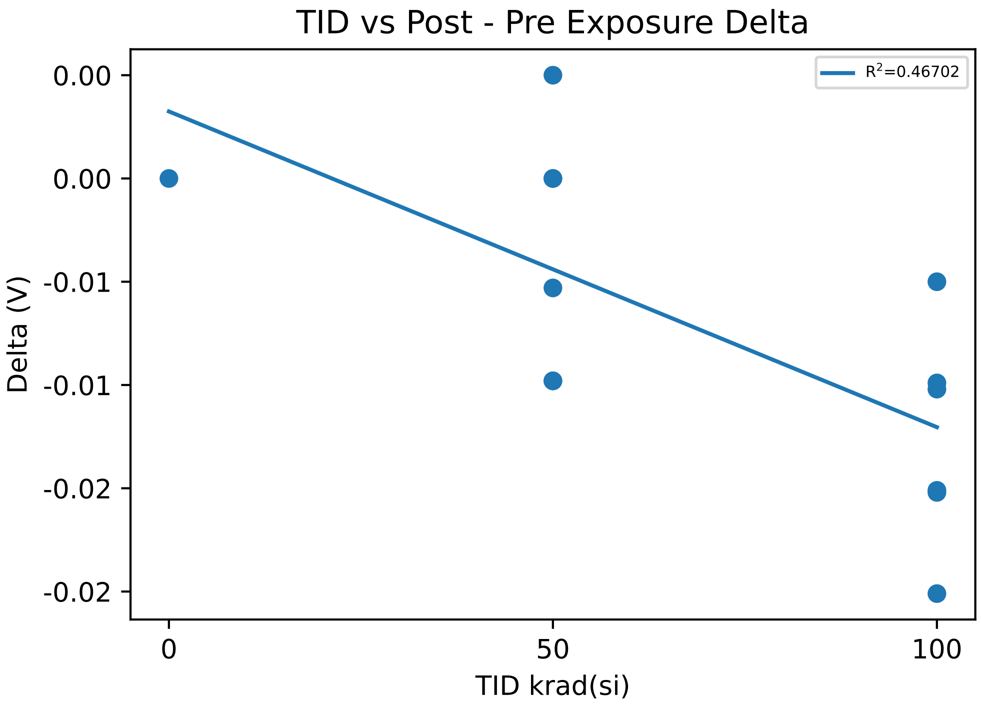
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.9995	4.9991	-0.0004
60	50	Biased	4.9993	4.9992	-0.0001
61	50	Biased	4.9996	4.9991	-0.0005
63	100	Biased	4.9994	4.9989	-0.0005
64	100	Biased	4.9993	4.9991	-0.0002
65	100	Biased	4.9994	4.9993	-0.0001
66	50	Unbiased	4.9996	4.9992	-0.0004
67	50	Unbiased	4.9994	4.9991	-0.0003
68	50	Unbiased	4.9995	4.9994	-0.0001
69	100	Unbiased	4.9994	4.999	-0.0004
70	100	Unbiased	4.9992	4.9993	0.0001
71	100	Unbiased	4.9996	4.9991	-0.0005
72	0	Control	4.9995	4.9994	-0.0001

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9995	4.9995	4.9995		4.9994	4.9994	4.9994		-0.0001	-0.0001	-0.0001	
50	4.9993	4.9995	4.9996	0.0001169	4.9991	4.9992	4.9994	0.0001169	-0.0005	-0.0003	-0.0001	0.00016733
100	4.9992	4.9994	4.9996	0.00013292	4.9989	4.9991	4.9993	0.00016021	-0.0005	-0.00026667	0.0001	0.00024221

Device Test: 80.1 UVLO BP5L Rise Thresh VIN_10V





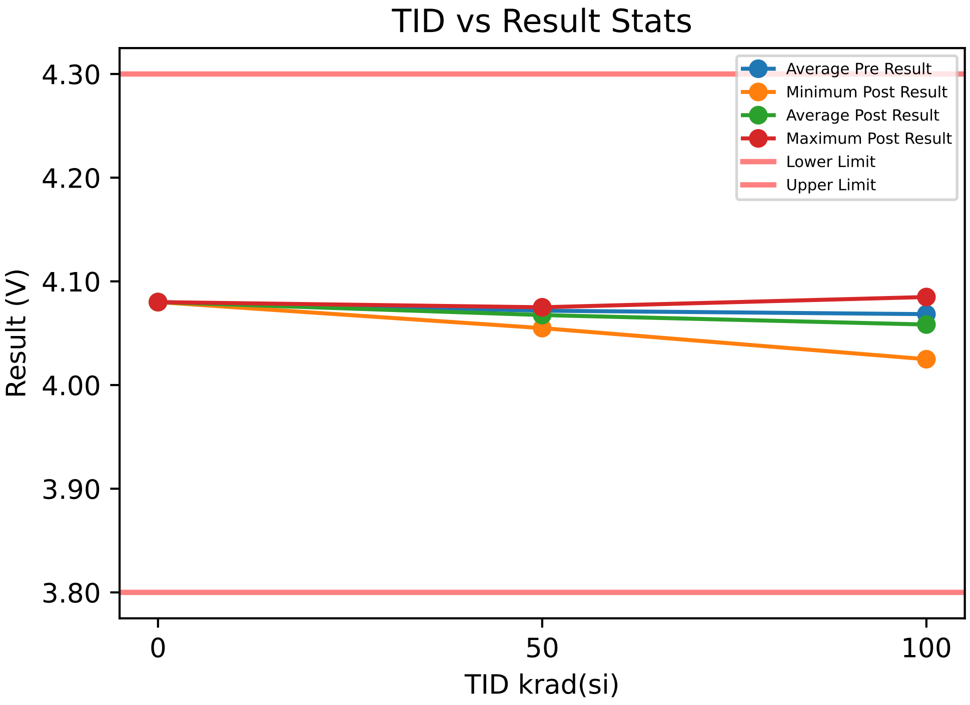
Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

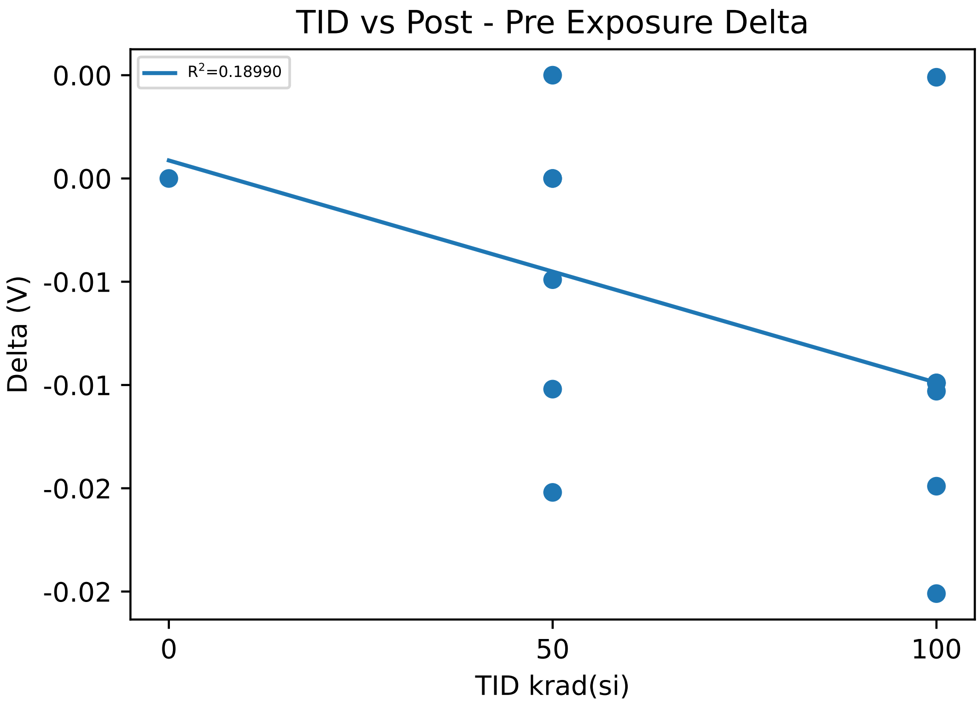
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.2599	4.2599	0
60	50	Biased	4.2648	4.255	-0.0098
61	50	Biased	4.2648	4.255	-0.0098
63	100	Biased	4.2751	4.2599	-0.0152
64	100	Biased	4.2701	4.255	-0.0151
65	100	Biased	4.305	4.2849	-0.0201
66	50	Unbiased	4.2701	4.2751	0.005
67	50	Unbiased	4.2701	4.2648	-0.0053
68	50	Unbiased	4.2751	4.2751	0
69	100	Unbiased	4.2701	4.2599	-0.0102
70	100	Unbiased	4.2299	4.22	-0.0099
71	100	Unbiased	4.2349	4.2299	-0.005
72	0	Control	4.28	4.28	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.28	4.28	4.28		4.28	4.28	4.28		0	0	0	
50	4.2599	4.2675	4.2751	0.0053594	4.255	4.2641	4.2751	0.0092275	-0.0098	-0.0033167	0.005	0.0059861
100	4.2299	4.2642	4.305	0.027886	4.22	4.2516	4.2849	0.023357	-0.0201	-0.012583	-0.005	0.0052928

Device Test: 80.2 UVLO BP5L Fall Thresh VIN_10V





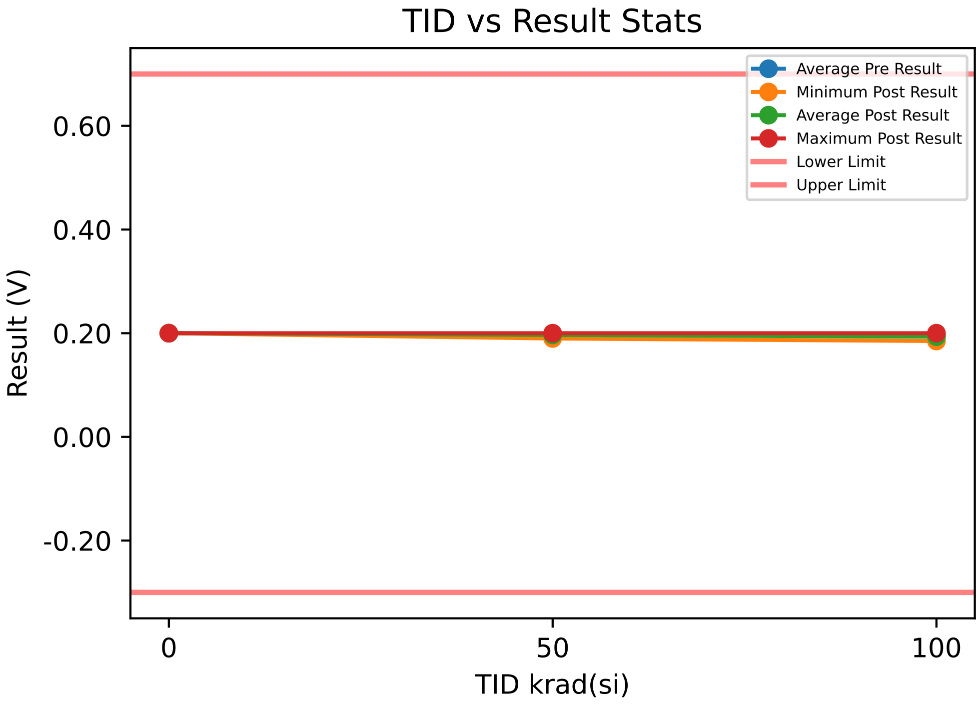
Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

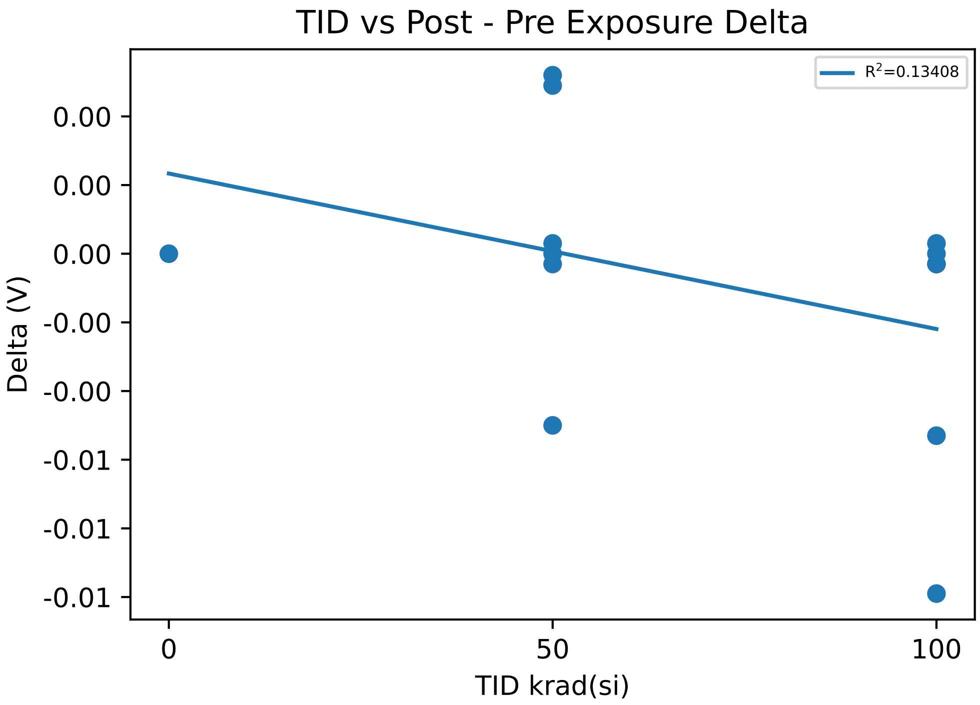
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.0651	4.0701	0.005
60	50	Biased	4.0701	4.0549	-0.0152
61	50	Biased	4.0701	4.0599	-0.0102
63	100	Biased	4.08	4.0651	-0.0149
64	100	Biased	4.075	4.0651	-0.0099
65	100	Biased	4.105	4.0849	-0.0201
66	50	Unbiased	4.075	4.075	0
67	50	Unbiased	4.075	4.0701	-0.0049
68	50	Unbiased	4.075	4.075	0
69	100	Unbiased	4.075	4.0651	-0.0099
70	100	Unbiased	4.0352	4.0249	-0.0103
71	100	Unbiased	4.0401	4.045	0.0049
72	0	Control	4.08	4.08	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.08	4.08	4.08		4.08	4.08	4.08		0	0	0	
50	4.0651	4.0717	4.075	0.0040336	4.0549	4.0675	4.075	0.008277	-0.0152	-0.0042167	0.005	0.0074486
100	4.0352	4.0684	4.105	0.026322	4.0249	4.0583	4.0849	0.020682	-0.0201	-0.010033	0.0049	0.0083443

Device Test: 80.3 UVLO BP5L Thresh Hysteresis VIN_10V





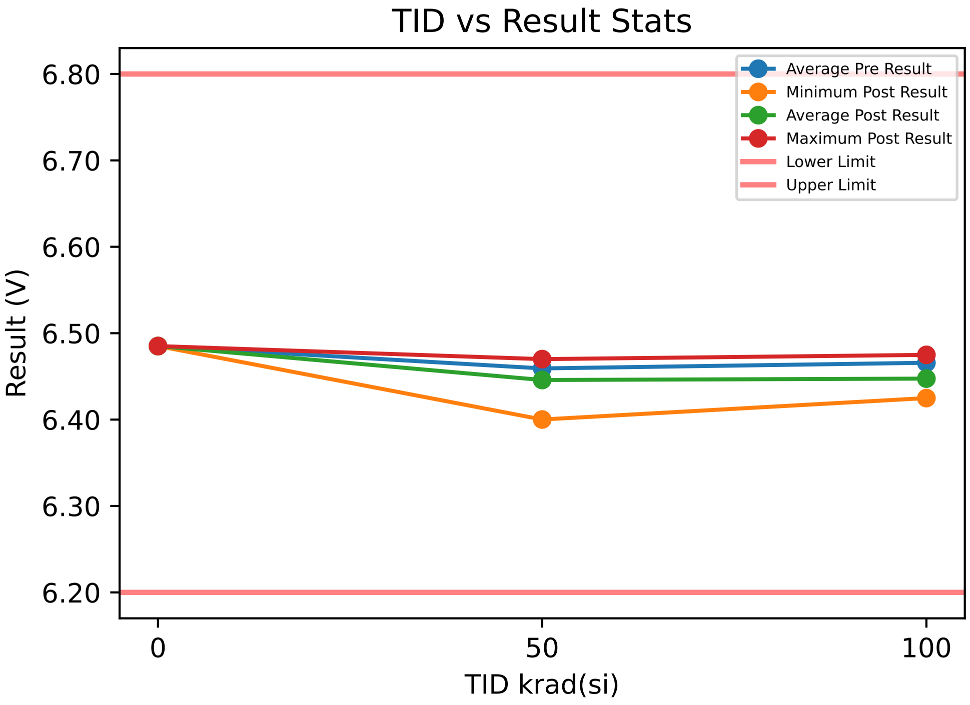
Test Results (Lower Limit = -0.3, Upper Limit = 0.7 (V))

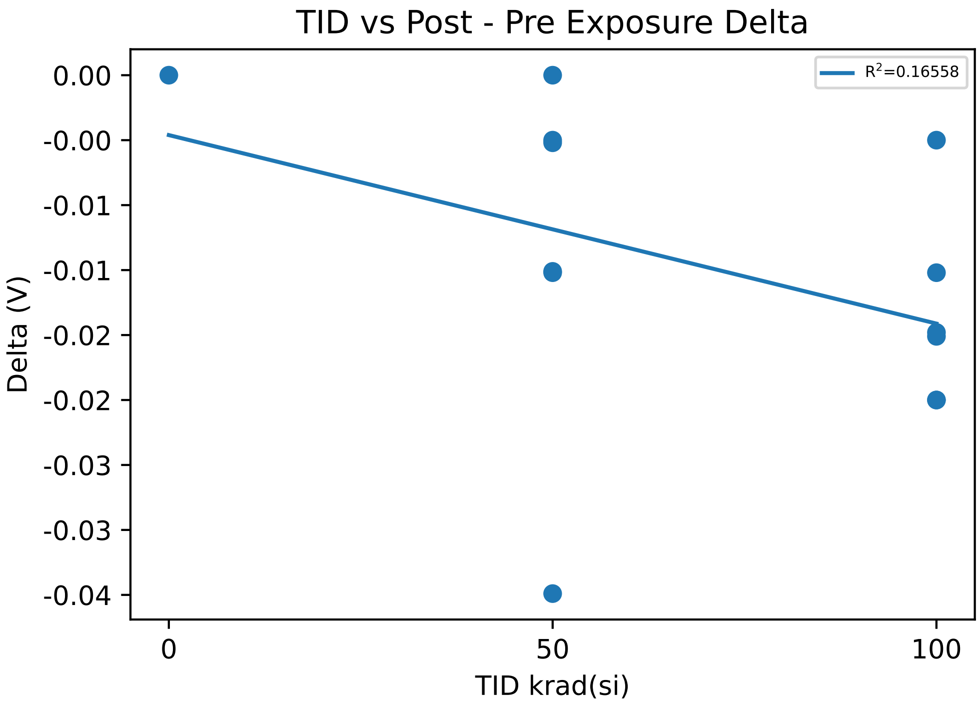
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.1948	0.1898	-0.005
60	50	Biased	0.1948	0.2	0.0052
61	50	Biased	0.1948	0.1951	0.0003
63	100	Biased	0.1951	0.1948	-0.0003
64	100	Biased	0.1951	0.1898	-0.0053
65	100	Biased	0.2	0.2	0
66	50	Unbiased	0.1951	0.2	0.0049
67	50	Unbiased	0.1951	0.1948	-0.0003
68	50	Unbiased	0.2	0.2	0
69	100	Unbiased	0.1951	0.1948	-0.0003
70	100	Unbiased	0.1948	0.1951	0.0003
71	100	Unbiased	0.1948	0.1849	-0.0099
72	0	Control	0.2	0.2	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2	0.2	0.2		0.2	0.2	0.2		0	0	0	
50	0.1948	0.19577	0.2	0.0020791	0.1898	0.19662	0.2	0.0041571	-0.005	0.00085	0.0052	0.003792
100	0.1948	0.19582	0.2	0.0020547	0.1849	0.19323	0.2	0.0052041	-0.0099	-0.0025833	0.0003	0.0041552

Device Test: 80.4 UVLO BP7L Rise Thresh VIN_10V





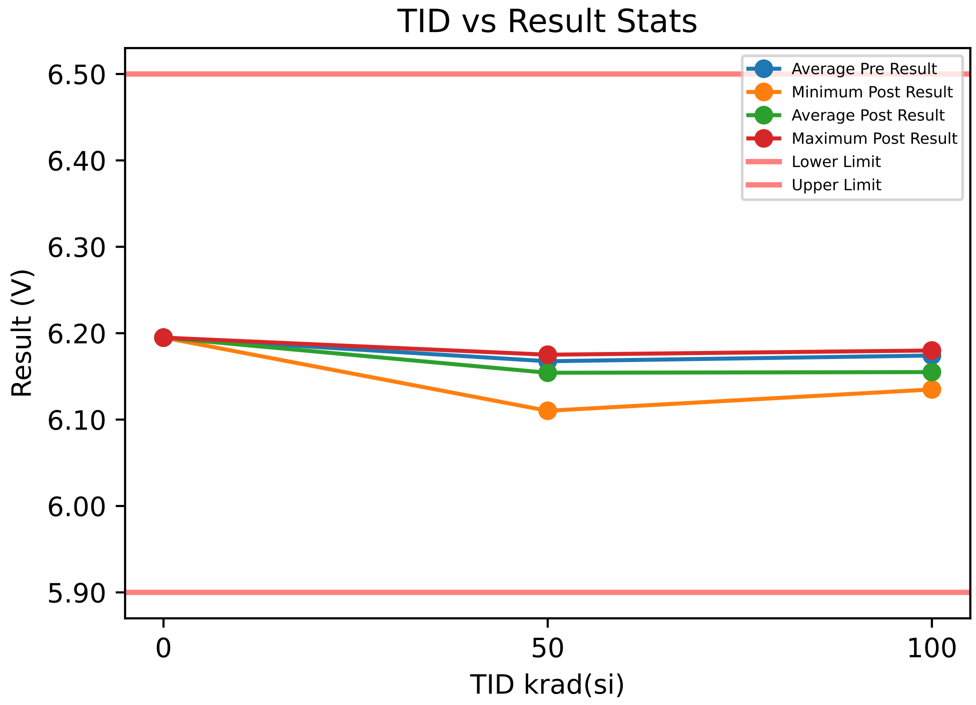
Test Results (Lower Limit = 6.2, Upper Limit = 6.8 (V))

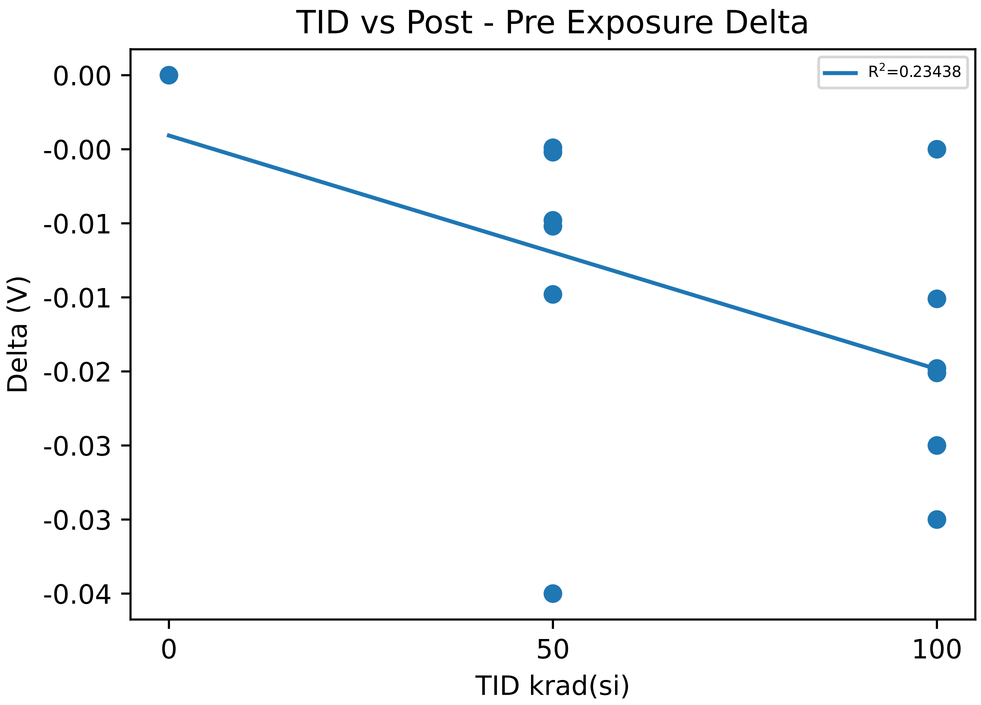
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.4051	6.4001	-0.005
60	50	Biased	6.47	6.4301	-0.0399
61	50	Biased	6.4851	6.47	-0.0151
63	100	Biased	6.4651	6.4499	-0.0152
64	100	Biased	6.4799	6.4601	-0.0198
65	100	Biased	6.4749	6.4499	-0.025
66	50	Unbiased	6.4651	6.4499	-0.0152
67	50	Unbiased	6.4601	6.4549	-0.0052
68	50	Unbiased	6.47	6.47	0
69	100	Unbiased	6.4799	6.4749	-0.005
70	100	Unbiased	6.445	6.4249	-0.0201
71	100	Unbiased	6.4499	6.4249	-0.025
72	0	Control	6.4851	6.4851	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.4851	6.4851	6.4851		6.4851	6.4851	6.4851		0	0	0	
50	6.4051	6.4592	6.4851	0.027808	6.4001	6.4458	6.47	0.026855	-0.0399	-0.0134	0	0.014323
100	6.445	6.4658	6.4799	0.015273	6.4249	6.4474	6.4749	0.019711	-0.025	-0.01835	-0.005	0.0075067

Device Test: 80.5 UVLO BP7L Fall Thresh VIN_10V





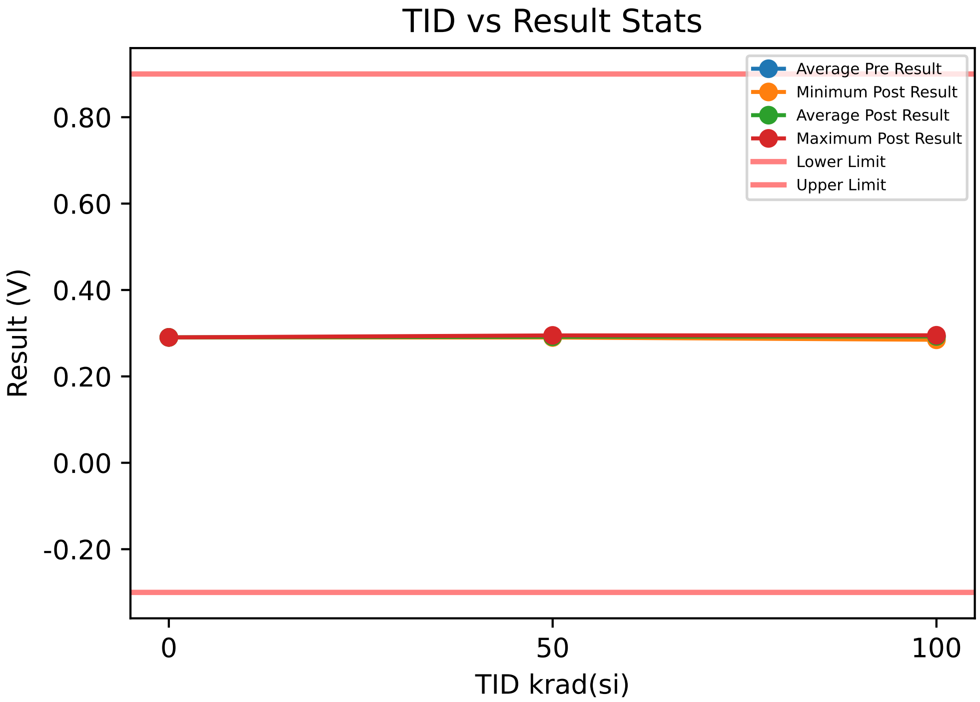
Test Results (Lower Limit = 5.9, Upper Limit = 6.5 (V))

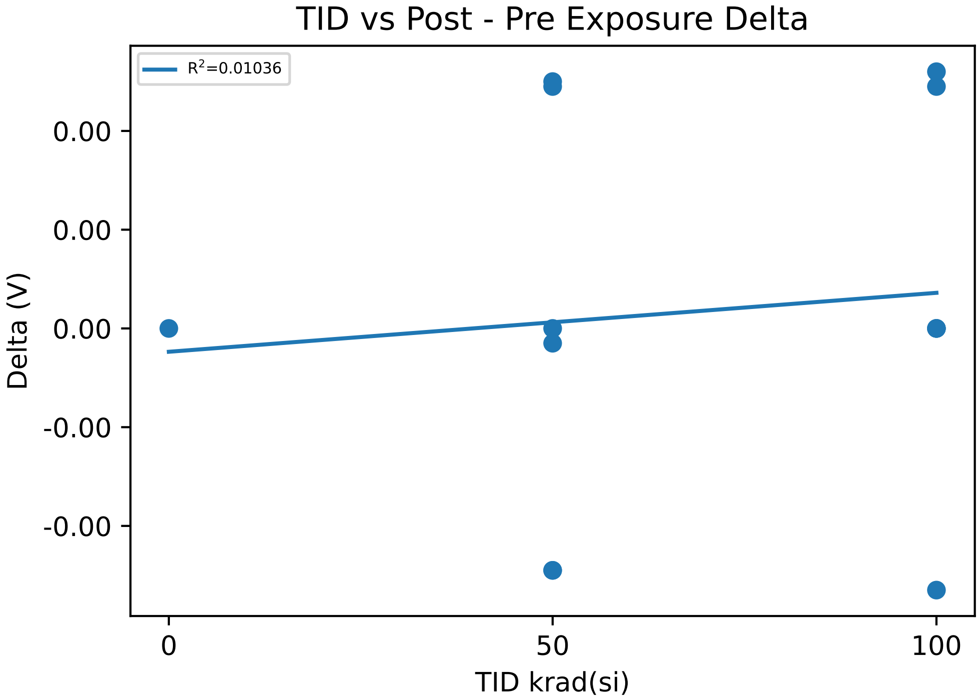
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.12	6.1102	-0.0098
60	50	Biased	6.1751	6.1401	-0.035
61	50	Biased	6.1899	6.1751	-0.0148
63	100	Biased	6.1701	6.155	-0.0151
64	100	Biased	6.1899	6.1649	-0.025
65	100	Biased	6.185	6.155	-0.03
66	50	Unbiased	6.1701	6.1599	-0.0102
67	50	Unbiased	6.1701	6.1649	-0.0052
68	50	Unbiased	6.18	6.1751	-0.0049
69	100	Unbiased	6.185	6.18	-0.005
70	100	Unbiased	6.155	6.1349	-0.0201
71	100	Unbiased	6.1599	6.1401	-0.0198
72	0	Control	6.1949	6.1949	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.1949	6.1949	6.1949		6.1949	6.1949	6.1949		0	0	0	
50	6.12	6.1675	6.1899	0.024436	6.1102	6.1542	6.1751	0.025121	-0.035	-0.013317	-0.0049	0.011235
100	6.155	6.1742	6.1899	0.014627	6.1349	6.155	6.18	0.016426	-0.03	-0.019167	-0.005	0.0086011

Device Test: 80.6 UVLO BP7L Thresh Hysteresis VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

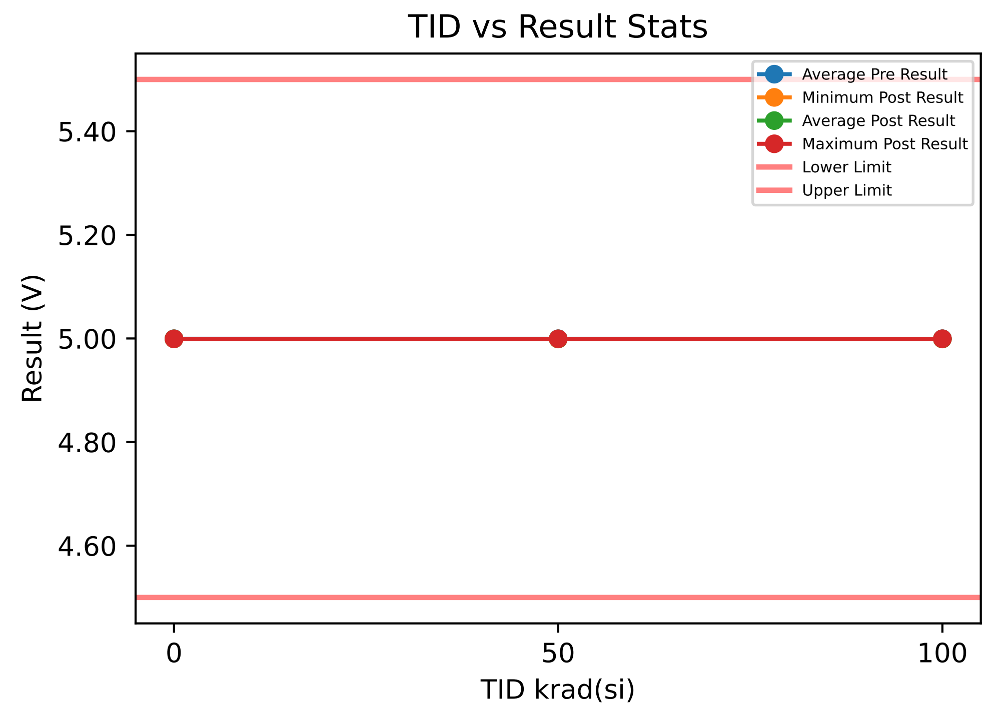
Test Results (Lower Limit = -0.3, Upper Limit = 0.9 (V))

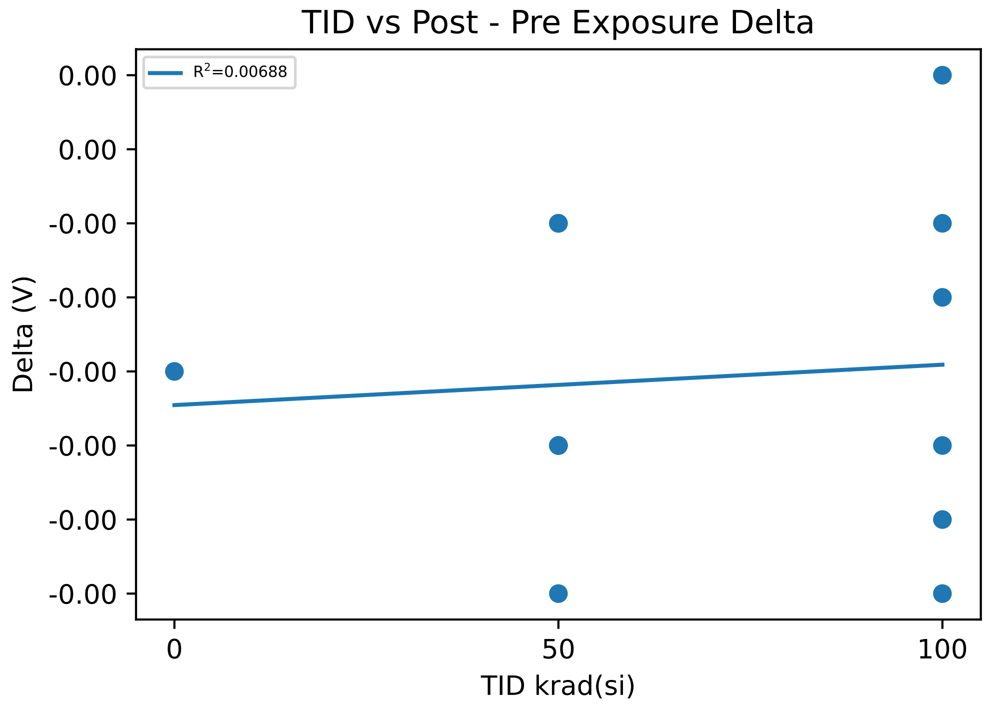
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.285	0.29	0.005
60	50	Biased	0.2949	0.29	-0.0049
61	50	Biased	0.2952	0.2949	-0.0003
63	100	Biased	0.2949	0.2949	0
64	100	Biased	0.29	0.2952	0.0052
65	100	Biased	0.29	0.2949	0.0049
66	50	Unbiased	0.2949	0.29	-0.0049
67	50	Unbiased	0.29	0.29	0
68	50	Unbiased	0.29	0.2949	0.0049
69	100	Unbiased	0.2949	0.2949	0
70	100	Unbiased	0.29	0.29	0
71	100	Unbiased	0.29	0.2847	-0.0053
72	0	Control	0.2903	0.2903	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2903	0.2903	0.2903		0.2903	0.2903	0.2903		0	0	0	
50	0.285	0.29167	0.2952	0.004084	0.29	0.29163	0.2949	0.0025303	-0.0049	-3.3333e-05	0.005	0.0044071
100	0.29	0.29163	0.2949	0.0025303	0.2847	0.29243	0.2952	0.004281	-0.0053	0.0008	0.0052	0.0038807

Device Test: 81.0 TM1 - LMUX V VIN_12V





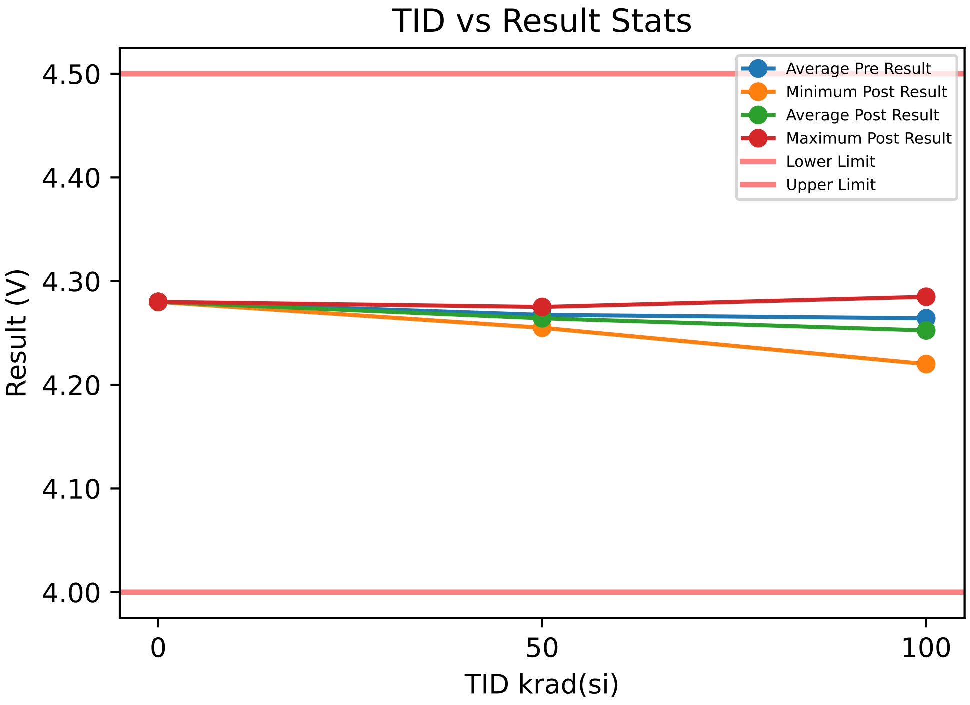
Test Results (Lower Limit = 4.5, Upper Limit = 5.5 (V))

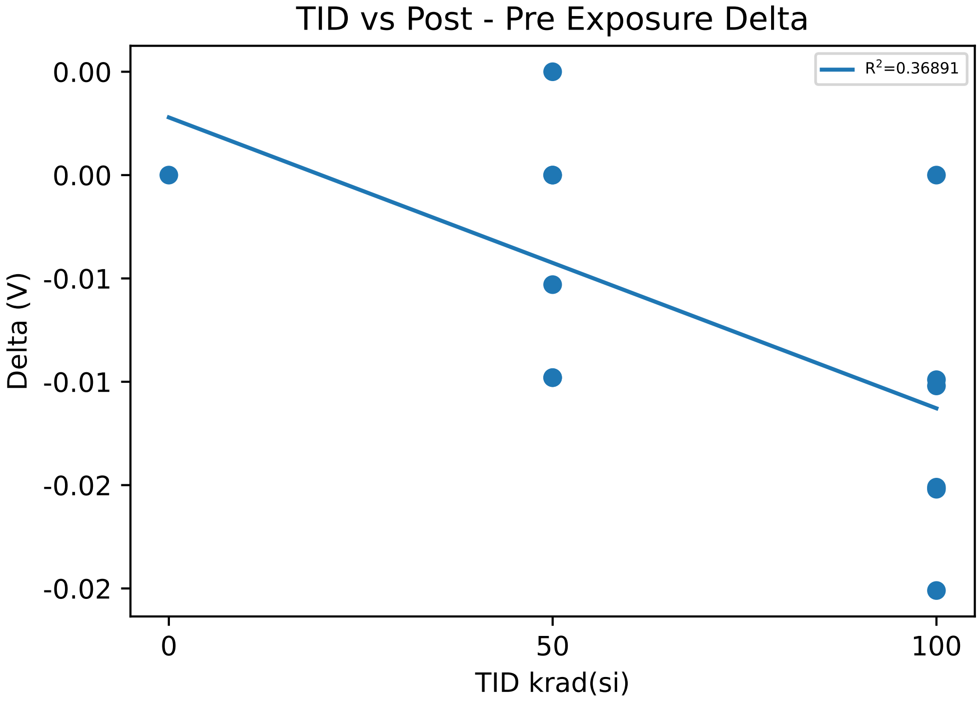
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.9996	4.999	-0.0006
60	50	Biased	4.9993	4.9992	-0.0001
61	50	Biased	4.9995	4.9991	-0.0004
63	100	Biased	4.9996	4.999	-0.0006
64	100	Biased	4.9993	4.9991	-0.0002
65	100	Biased	4.9995	4.9994	-0.0001
66	50	Unbiased	4.9994	4.9993	-0.0001
67	50	Unbiased	4.9995	4.9991	-0.0004
68	50	Unbiased	4.9995	4.9991	-0.0004
69	100	Unbiased	4.9995	4.9991	-0.0004
70	100	Unbiased	4.9992	4.9993	0.0001
71	100	Unbiased	4.9995	4.999	-0.0005
72	0	Control	4.9995	4.9992	-0.0003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9995	4.9995	4.9995		4.9992	4.9992	4.9992		-0.0003	-0.0003	-0.0003	
50	4.9993	4.9995	4.9996	0.00010328	4.999	4.9991	4.9993	0.00010328	-0.0006	-0.00033333	-0.0001	0.00019664
100	4.9992	4.9994	4.9996	0.00015055	4.999	4.9992	4.9994	0.00016432	-0.0006	-0.00028333	0.0001	0.00026394

Device Test: 81.1 UVLO BP5L Rise Thresh VIN_12V





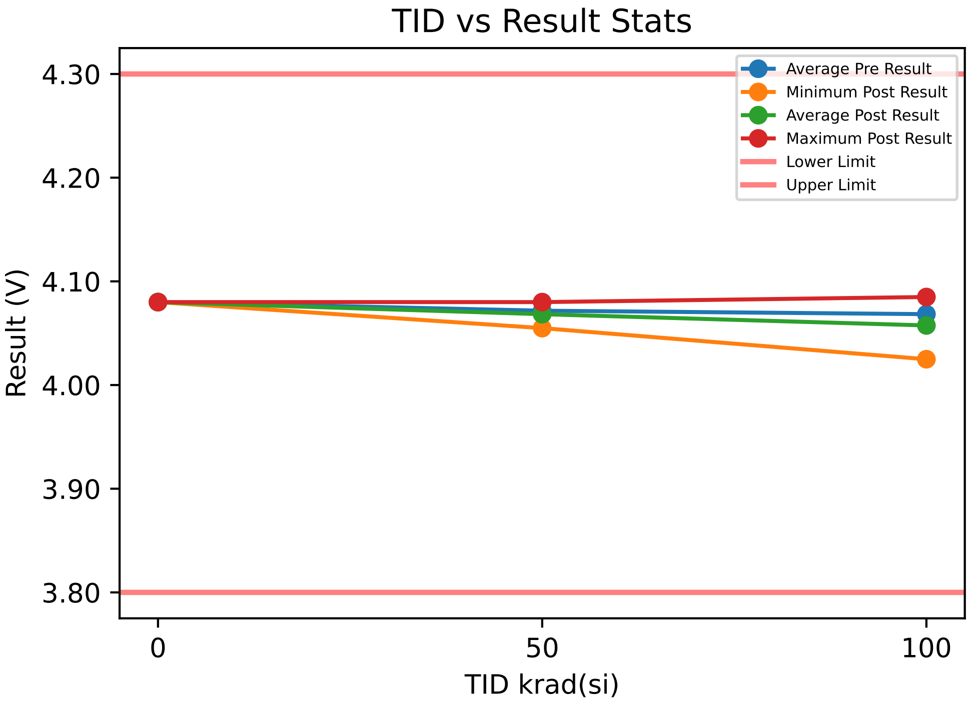
Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

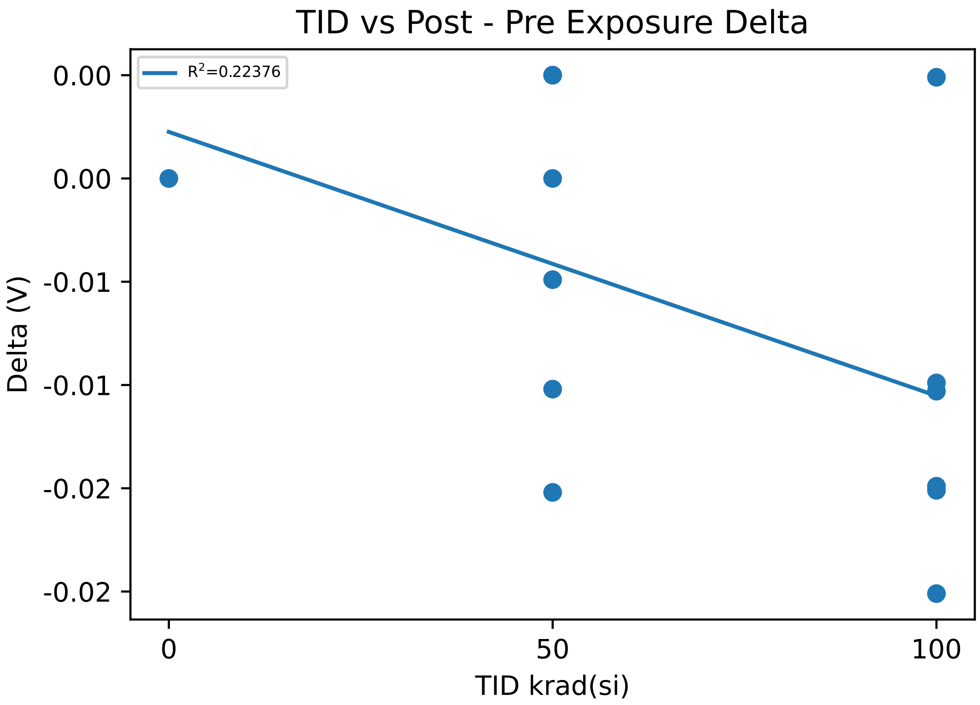
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.2599	4.2599	0
60	50	Biased	4.2648	4.255	-0.0098
61	50	Biased	4.2648	4.255	-0.0098
63	100	Biased	4.2751	4.2599	-0.0152
64	100	Biased	4.2701	4.255	-0.0151
65	100	Biased	4.305	4.2849	-0.0201
66	50	Unbiased	4.2701	4.2751	0.005
67	50	Unbiased	4.2701	4.2648	-0.0053
68	50	Unbiased	4.2751	4.2751	0
69	100	Unbiased	4.2701	4.2599	-0.0102
70	100	Unbiased	4.2299	4.22	-0.0099
71	100	Unbiased	4.2349	4.2349	0
72	0	Control	4.28	4.28	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.28	4.28	4.28		4.28	4.28	4.28		0	0	0	
50	4.2599	4.2675	4.2751	0.0053594	4.255	4.2641	4.2751	0.0092275	-0.0098	-0.0033167	0.005	0.0059861
100	4.2299	4.2642	4.305	0.027886	4.22	4.2524	4.2849	0.022501	-0.0201	-0.01175	0	0.0068809

Device Test: 81.2 UVLO BP5L Fall Thresh VIN_12V





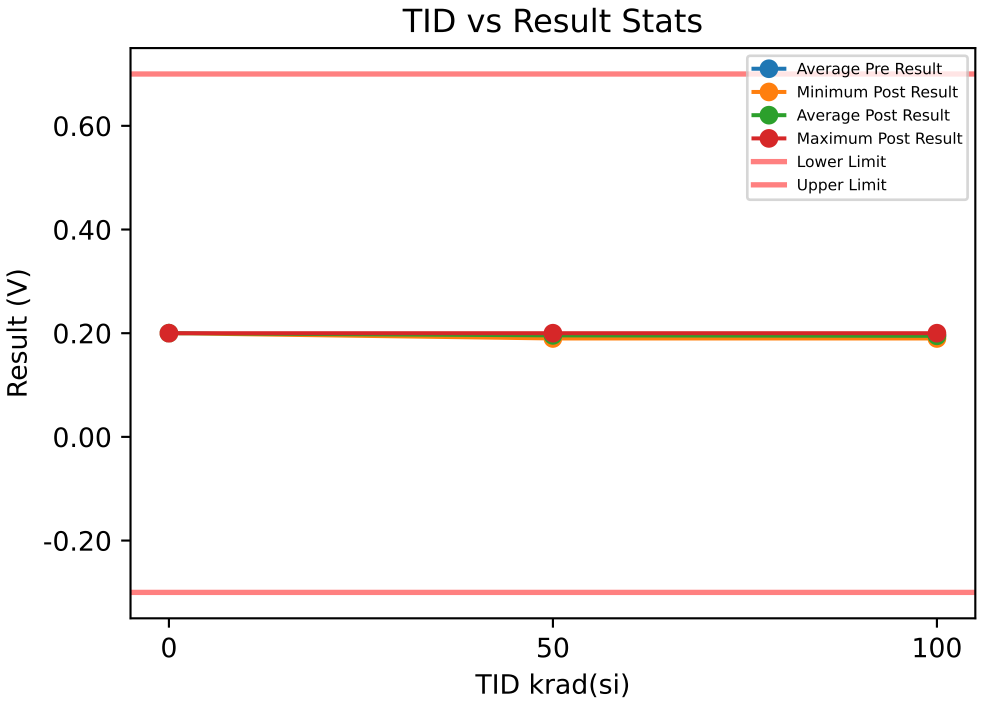
Test Results (Lower Limit = 3.8,
Upper Limit = 4.3 (V))

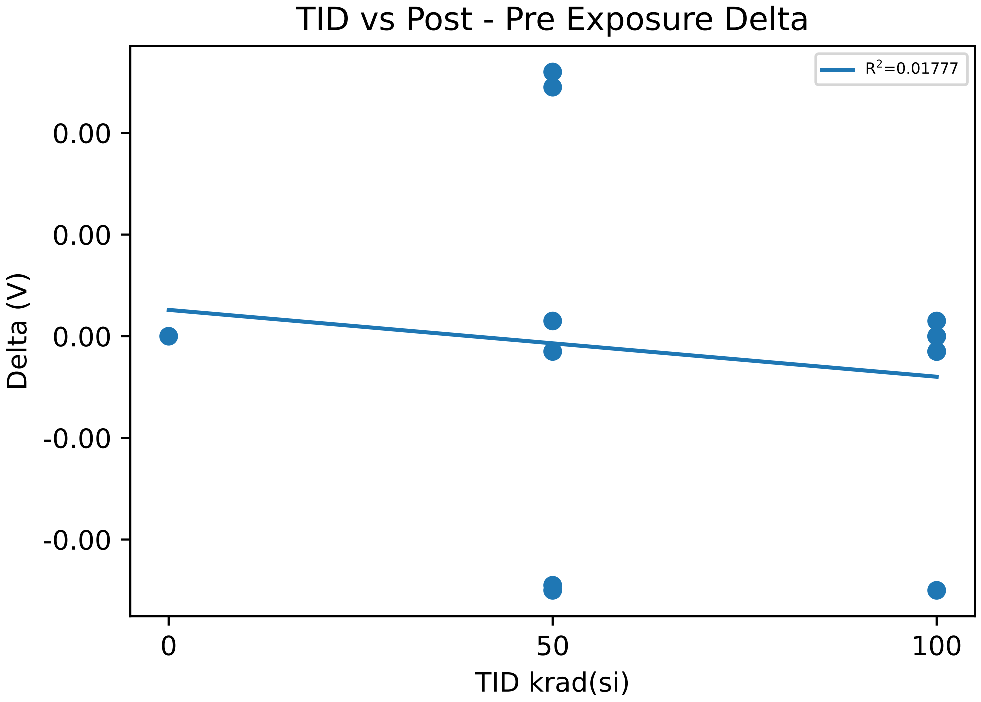
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.0651	4.0701	0.005
60	50	Biased	4.0701	4.0549	-0.0152
61	50	Biased	4.0701	4.0599	-0.0102
63	100	Biased	4.08	4.0651	-0.0149
64	100	Biased	4.075	4.0599	-0.0151
65	100	Biased	4.105	4.0849	-0.0201
66	50	Unbiased	4.075	4.075	0
67	50	Unbiased	4.075	4.0701	-0.0049
68	50	Unbiased	4.075	4.08	0.005
69	100	Unbiased	4.075	4.0651	-0.0099
70	100	Unbiased	4.0352	4.0249	-0.0103
71	100	Unbiased	4.0401	4.045	0.0049
72	0	Control	4.08	4.08	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.08	4.08	4.08		4.08	4.08	4.08		0	0	0	
50	4.0651	4.0717	4.075	0.0040336	4.0549	4.0683	4.08	0.0093635	-0.0152	-0.0033833	0.005	0.0082512
100	4.0352	4.0684	4.105	0.026322	4.0249	4.0575	4.0849	0.02045	-0.0201	-0.0109	0.0049	0.008594

Device Test: 81.3 UVLO BP5L Thresh Hysteresis VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

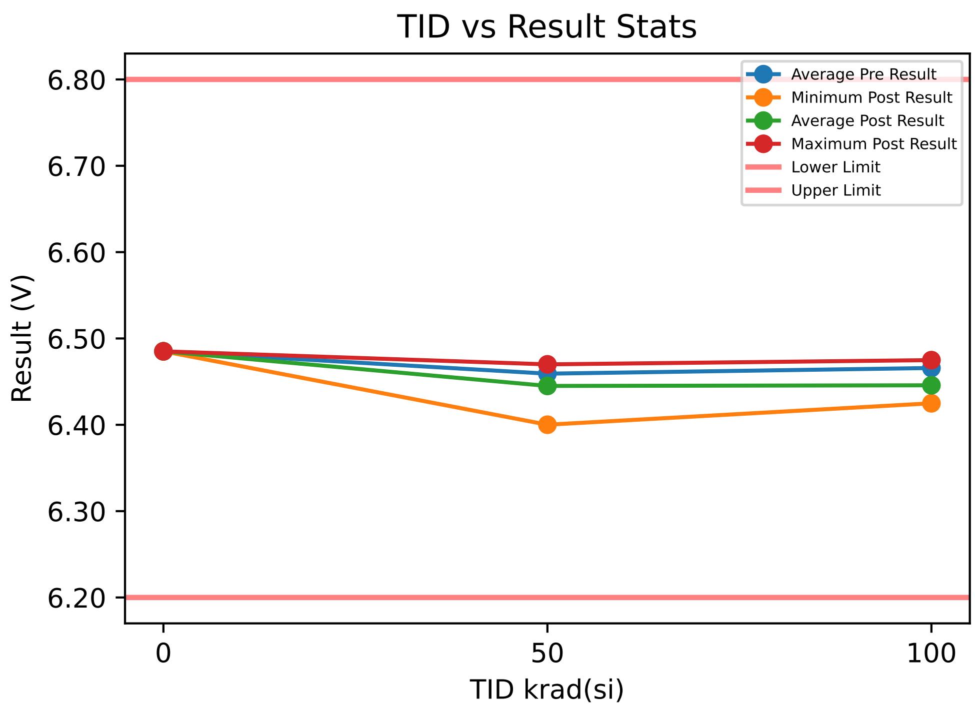
Test Results (Lower Limit = -0.3, Upper Limit = 0.7 (V))

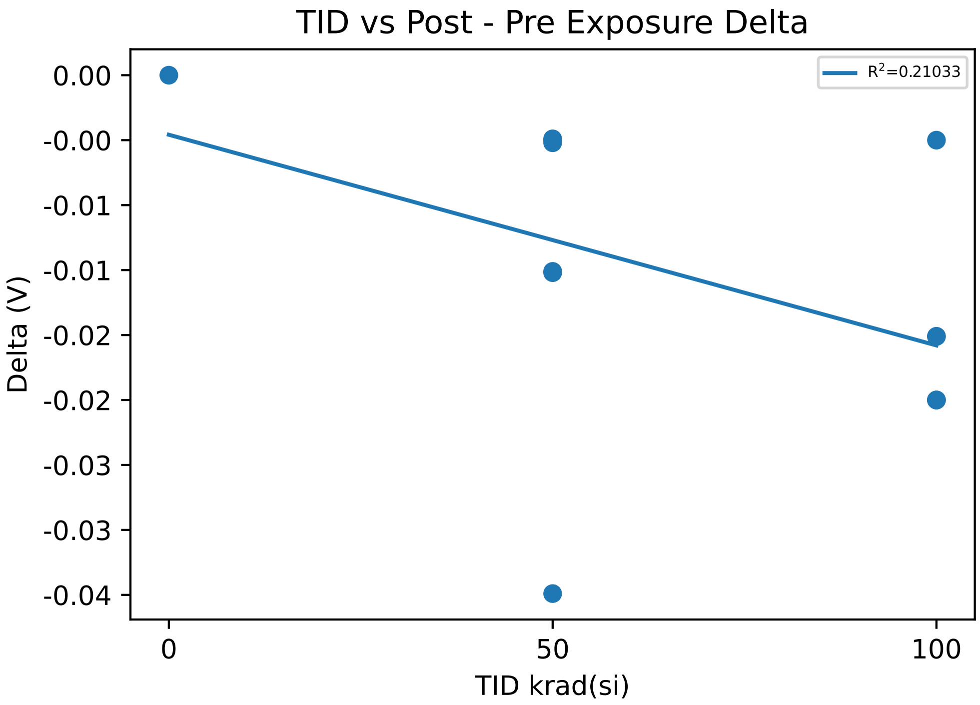
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.1948	0.1898	-0.005
60	50	Biased	0.1948	0.2	0.0052
61	50	Biased	0.1948	0.1951	0.0003
63	100	Biased	0.1951	0.1948	-0.0003
64	100	Biased	0.1951	0.1951	0
65	100	Biased	0.2	0.2	0
66	50	Unbiased	0.1951	0.2	0.0049
67	50	Unbiased	0.1951	0.1948	-0.0003
68	50	Unbiased	0.2	0.1951	-0.0049
69	100	Unbiased	0.1951	0.1948	-0.0003
70	100	Unbiased	0.1948	0.1951	0.0003
71	100	Unbiased	0.1948	0.1898	-0.005
72	0	Control	0.2	0.2	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2	0.2	0.2		0.2	0.2	0.2		0	0	0	
50	0.1948	0.19577	0.2	0.0020791	0.1898	0.1958	0.2	0.0038278	-0.005	3.3333e-05	0.0052	0.0044774
100	0.1948	0.19582	0.2	0.0020547	0.1898	0.19493	0.2	0.0032284	-0.005	-0.00088333	0.0003	0.0020292

Device Test: 81.4 UVLO BP7L Rise Thresh VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

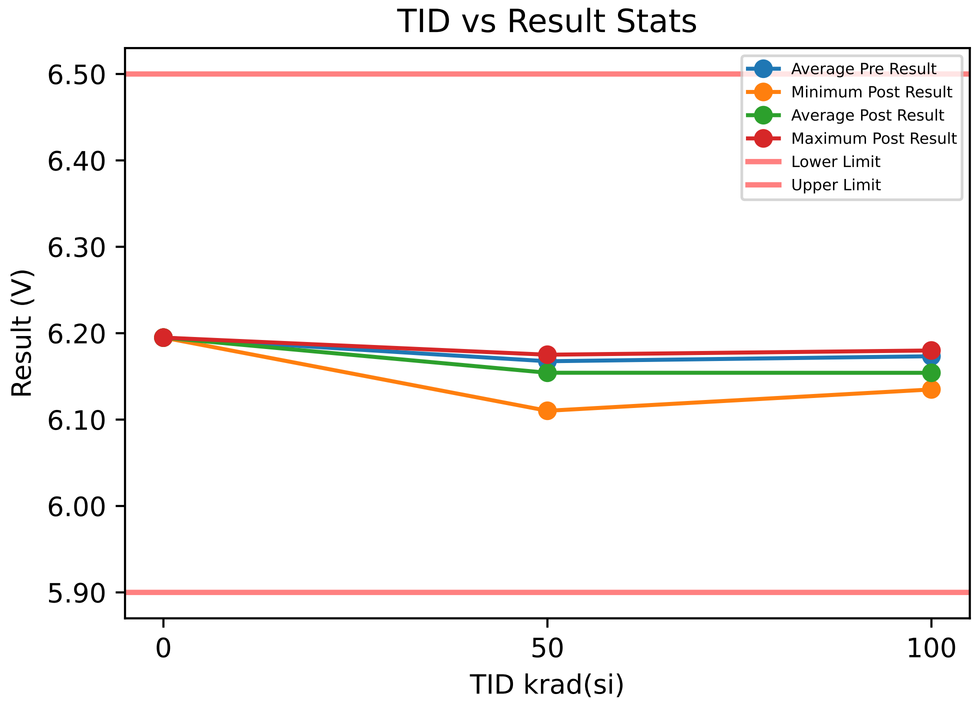
Test Results (Lower Limit = 6.2, Upper Limit = 6.8 (V))

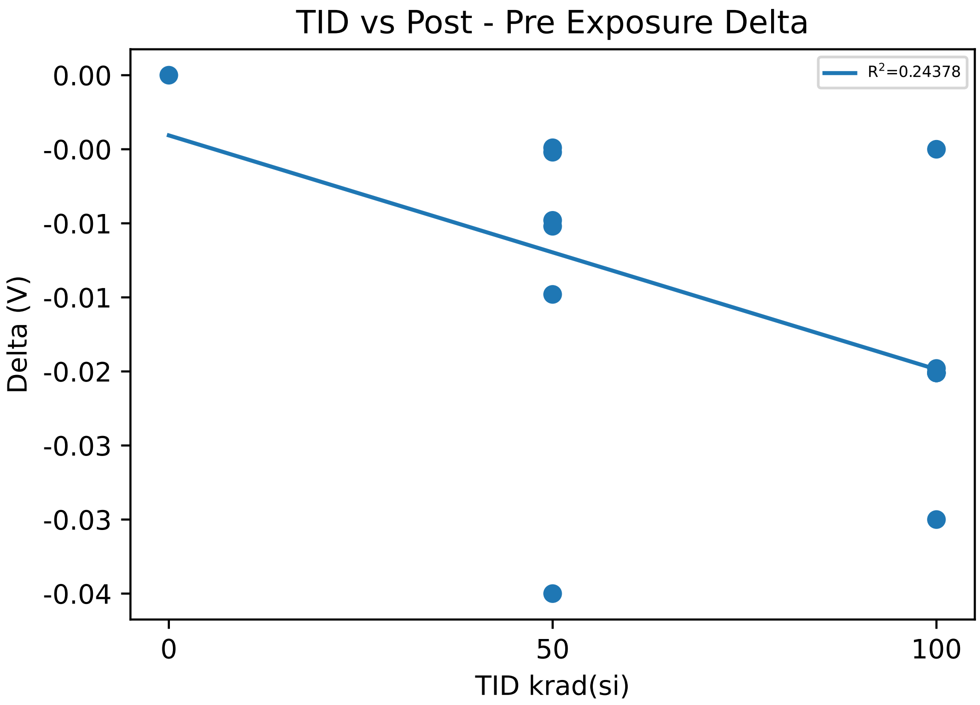
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.4051	6.4001	-0.005
60	50	Biased	6.47	6.4301	-0.0399
61	50	Biased	6.4851	6.47	-0.0151
63	100	Biased	6.4651	6.445	-0.0201
64	100	Biased	6.4799	6.4549	-0.025
65	100	Biased	6.4749	6.4499	-0.025
66	50	Unbiased	6.4651	6.4499	-0.0152
67	50	Unbiased	6.4601	6.4549	-0.0052
68	50	Unbiased	6.47	6.4651	-0.0049
69	100	Unbiased	6.4799	6.4749	-0.005
70	100	Unbiased	6.445	6.4249	-0.0201
71	100	Unbiased	6.4499	6.4249	-0.025
72	0	Control	6.4851	6.4851	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.4851	6.4851	6.4851		6.4851	6.4851	6.4851		0	0	0	
50	6.4051	6.4592	6.4851	0.027808	6.4001	6.445	6.47	0.026035	-0.0399	-0.014217	-0.0049	0.013524
100	6.445	6.4658	6.4799	0.015273	6.4249	6.4458	6.4749	0.019082	-0.025	-0.020033	-0.005	0.0077461

Device Test: 81.5 UVLO BP7L Fall Thresh VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

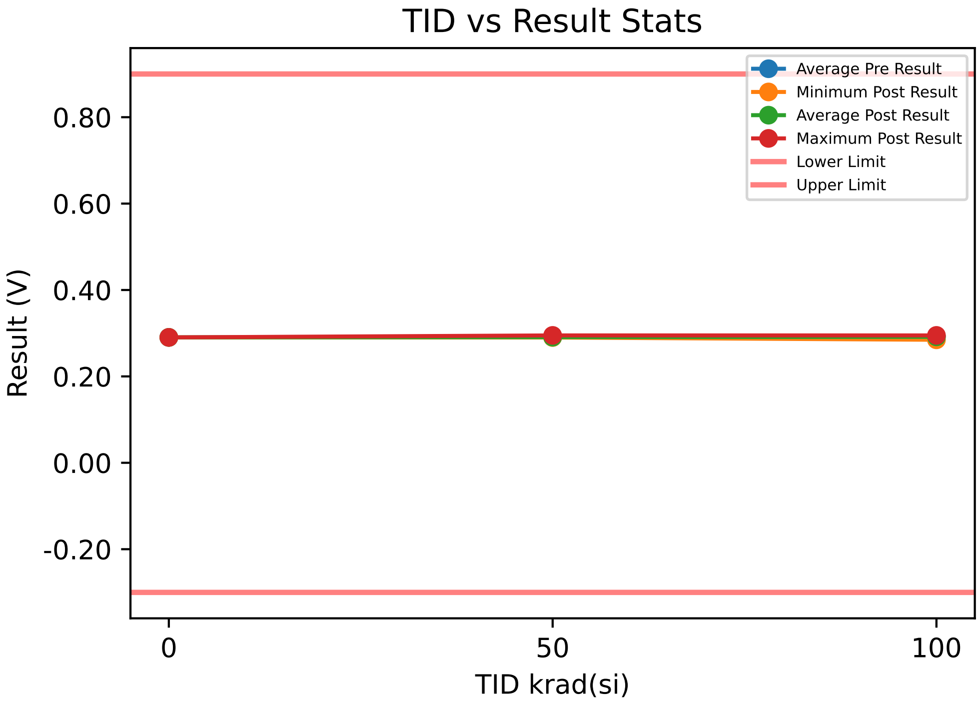
Test Results (Lower Limit = 5.9, Upper Limit = 6.5 (V))

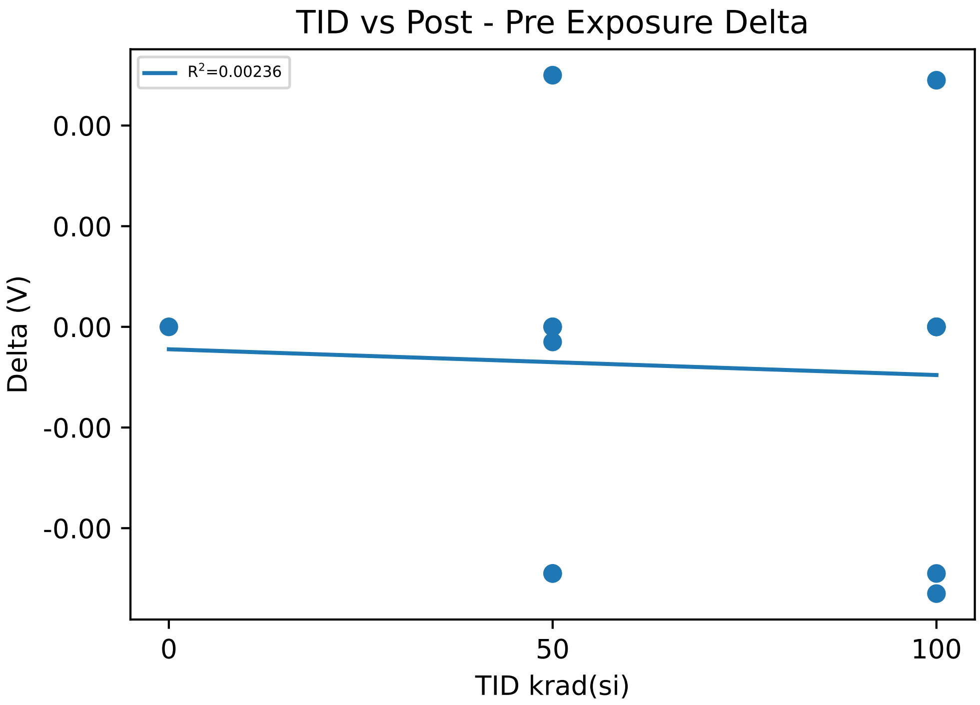
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.12	6.1102	-0.0098
60	50	Biased	6.1751	6.1401	-0.035
61	50	Biased	6.1899	6.1751	-0.0148
63	100	Biased	6.1701	6.15	-0.0201
64	100	Biased	6.185	6.1649	-0.0201
65	100	Biased	6.185	6.155	-0.03
66	50	Unbiased	6.1701	6.1599	-0.0102
67	50	Unbiased	6.1701	6.1649	-0.0052
68	50	Unbiased	6.18	6.1751	-0.0049
69	100	Unbiased	6.185	6.18	-0.005
70	100	Unbiased	6.155	6.1349	-0.0201
71	100	Unbiased	6.1599	6.1401	-0.0198
72	0	Control	6.1949	6.1949	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.1949	6.1949	6.1949		6.1949	6.1949	6.1949		0	0	0	
50	6.12	6.1675	6.1899	0.024436	6.1102	6.1542	6.1751	0.025121	-0.035	-0.013317	-0.0049	0.011235
100	6.155	6.1733	6.185	0.013677	6.1349	6.1542	6.18	0.016551	-0.03	-0.019183	-0.005	0.0080133

Device Test: 81.6 UVLO BP7L Thresh Hysteresis VIN_12V





Test Results (Lower Limit = -0.3, Upper Limit = 0.9 (V))

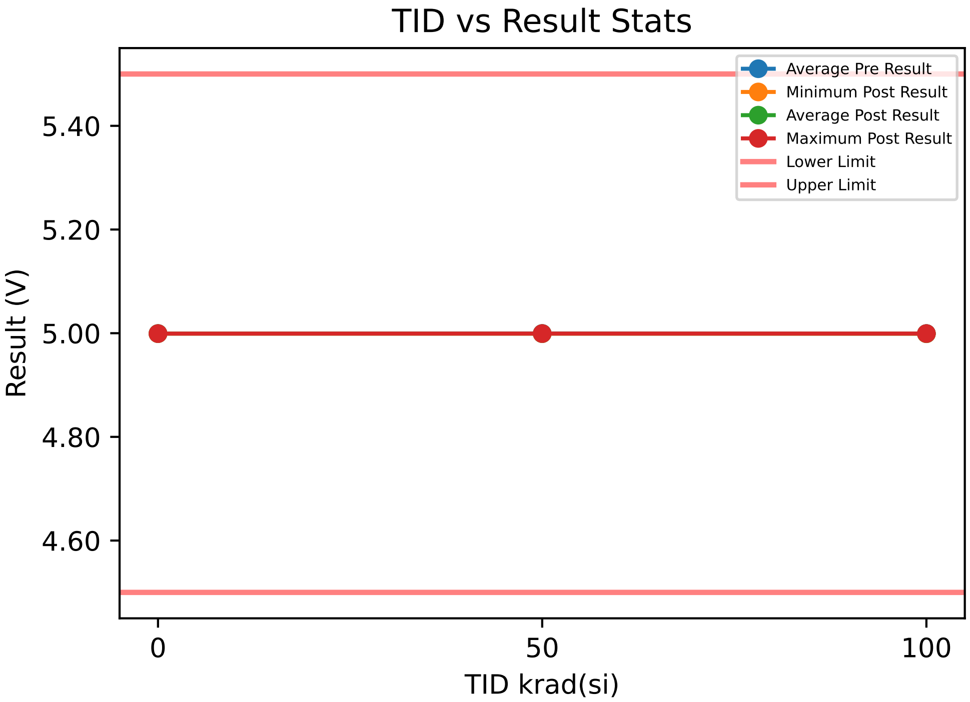
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.285	0.29	0.005
60	50	Biased	0.2949	0.29	-0.0049
61	50	Biased	0.2952	0.2949	-0.0003
63	100	Biased	0.2949	0.2949	0
64	100	Biased	0.2949	0.29	-0.0049
65	100	Biased	0.29	0.2949	0.0049
66	50	Unbiased	0.2949	0.29	-0.0049
67	50	Unbiased	0.29	0.29	0
68	50	Unbiased	0.29	0.29	0
69	100	Unbiased	0.2949	0.2949	0
70	100	Unbiased	0.29	0.29	0
71	100	Unbiased	0.29	0.2847	-0.0053
72	0	Control	0.2903	0.2903	0

Test Statistics (V)

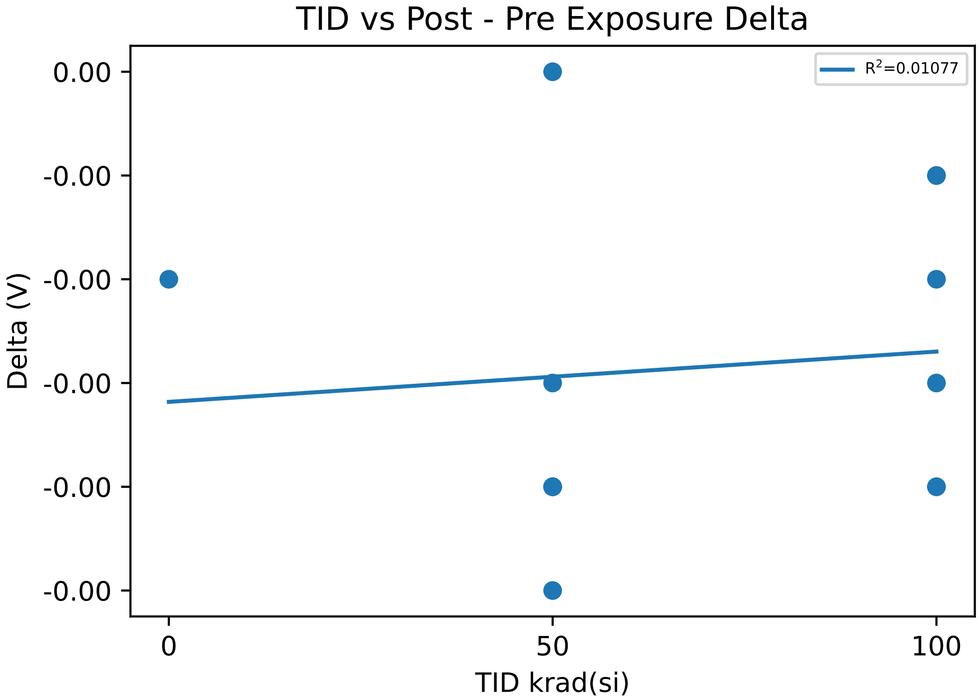
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2903	0.2903	0.2903		0.2903	0.2903	0.2903		0	0	0	
50	0.285	0.29167	0.2952	0.004084	0.29	0.29082	0.2949	0.0020004	-0.0049	-0.00085	0.005	0.0037088
100	0.29	0.29245	0.2949	0.0026838	0.2847	0.29157	0.2949	0.0041326	-0.0053	-0.00088333	0.0049	0.0037796

Device Test: 82.0 TM1 - LMUX V VIN_14V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



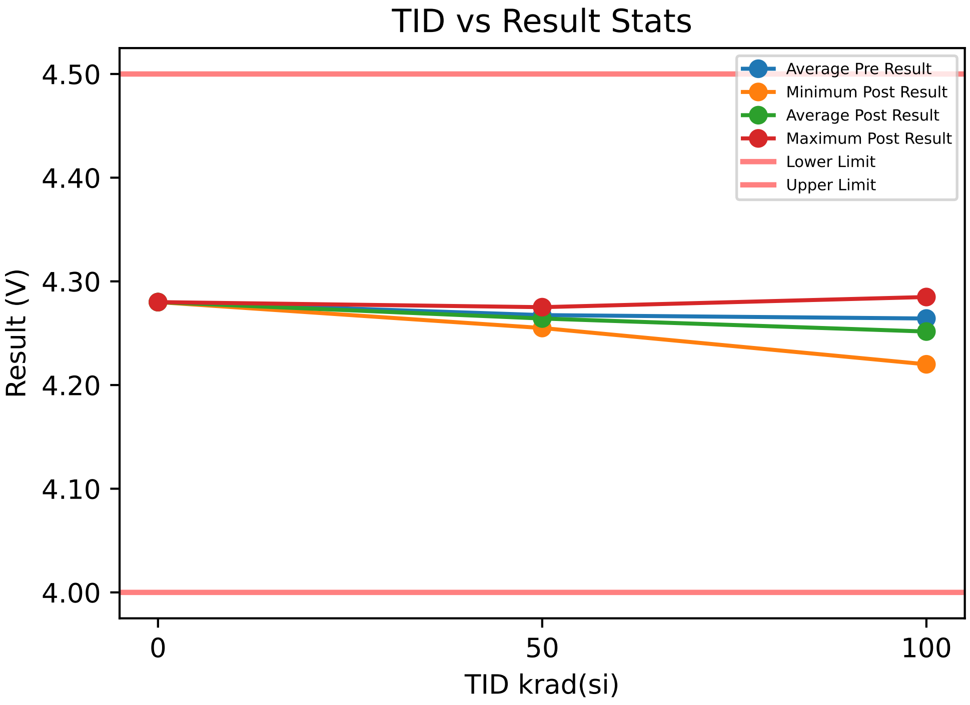
Test Results (Lower Limit = 4.5, Upper Limit = 5.5 (V))

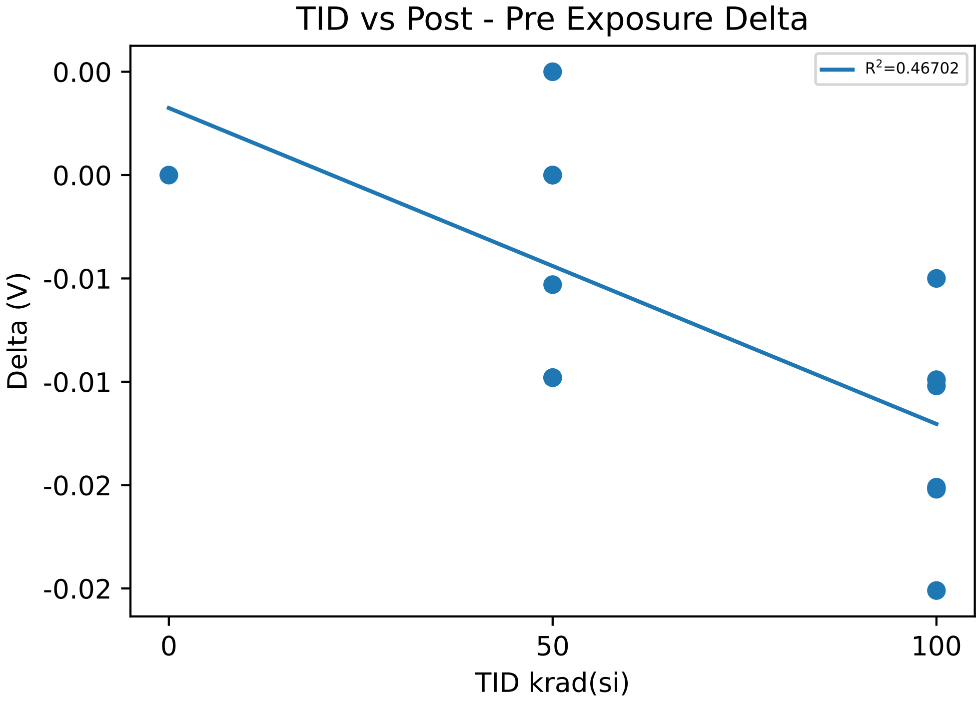
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.9996	4.9992	-0.0004
60	50	Biased	4.9993	4.9993	0
61	50	Biased	4.9996	4.9991	-0.0005
63	100	Biased	4.9994	4.999	-0.0004
64	100	Biased	4.9993	4.9991	-0.0002
65	100	Biased	4.9994	4.9993	-0.0001
66	50	Unbiased	4.9996	4.9992	-0.0004
67	50	Unbiased	4.9995	4.9992	-0.0003
68	50	Unbiased	4.9996	4.9992	-0.0004
69	100	Unbiased	4.9995	4.9992	-0.0003
70	100	Unbiased	4.9992	4.9991	-0.0001
71	100	Unbiased	4.9995	4.9991	-0.0004
72	0	Control	4.9994	4.9992	-0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9994	4.9994	4.9994		4.9992	4.9992	4.9992		-0.0002	-0.0002	-0.0002	
50	4.9993	4.9995	4.9996	0.00012111	4.9991	4.9992	4.9993	6.3246e-05	-0.0005	-0.00033333	0	0.00017512
100	4.9992	4.9994	4.9995	0.0001169	4.999	4.9991	4.9993	0.00010328	-0.0004	-0.00025	-0.0001	0.00013784

Device Test: 82.1 UVLO BP5L Rise Thresh VIN_14V





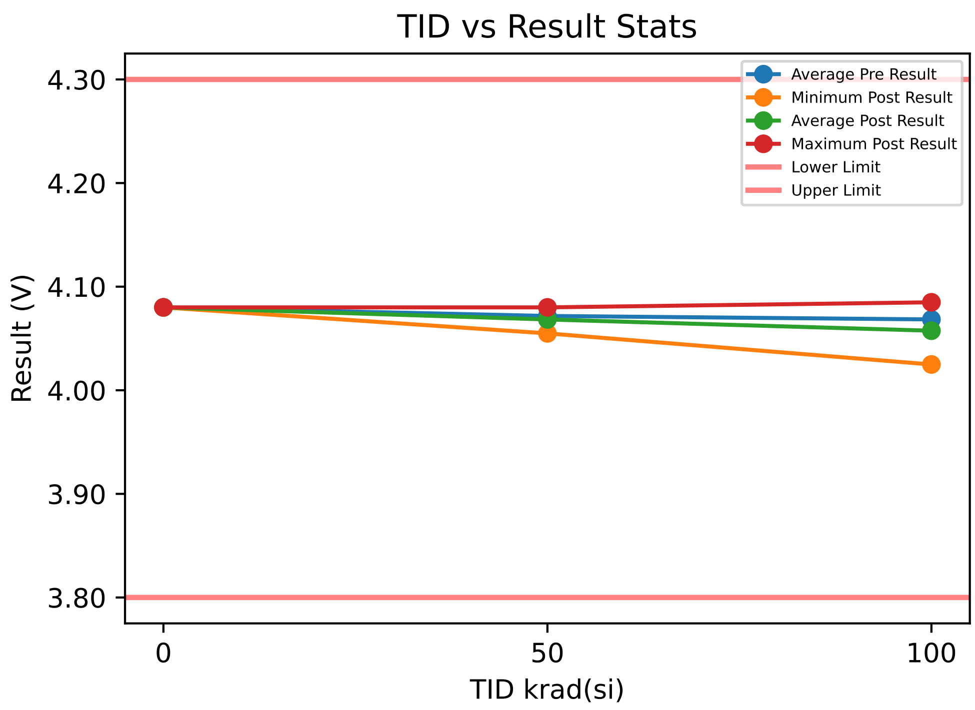
Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

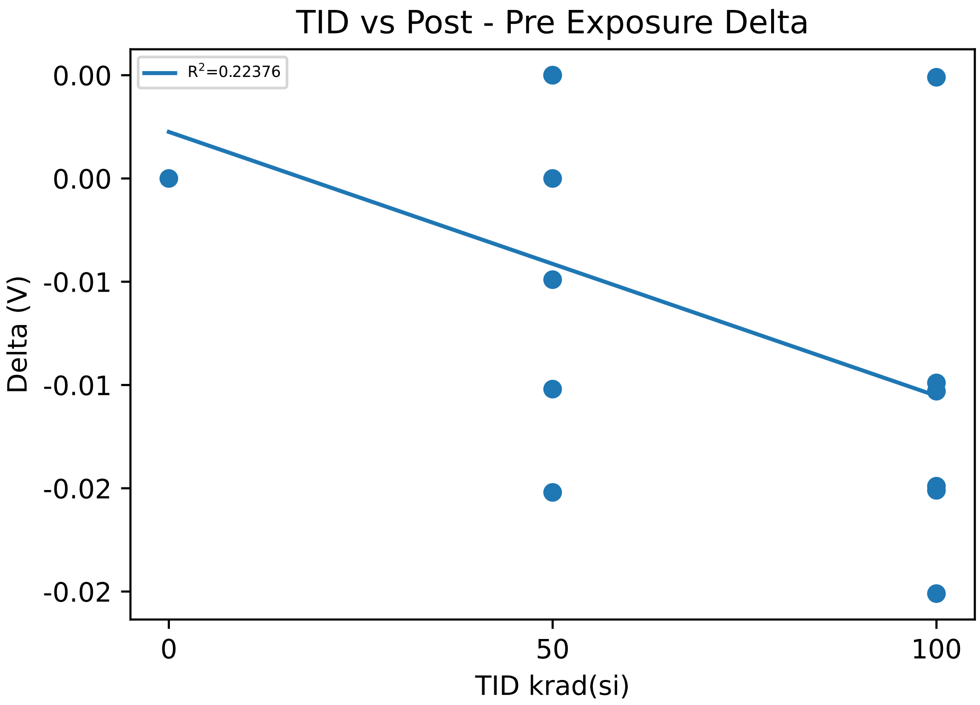
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.2599	4.2599	0
60	50	Biased	4.2648	4.255	-0.0098
61	50	Biased	4.2648	4.255	-0.0098
63	100	Biased	4.2751	4.2599	-0.0152
64	100	Biased	4.2701	4.255	-0.0151
65	100	Biased	4.305	4.2849	-0.0201
66	50	Unbiased	4.2701	4.2751	0.005
67	50	Unbiased	4.2701	4.2648	-0.0053
68	50	Unbiased	4.2751	4.2751	0
69	100	Unbiased	4.2701	4.2599	-0.0102
70	100	Unbiased	4.2299	4.22	-0.0099
71	100	Unbiased	4.2349	4.2299	-0.005
72	0	Control	4.28	4.28	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.28	4.28	4.28		4.28	4.28	4.28		0	0	0	
50	4.2599	4.2675	4.2751	0.0053594	4.255	4.2641	4.2751	0.0092275	-0.0098	-0.0033167	0.005	0.0059861
100	4.2299	4.2642	4.305	0.027886	4.22	4.2516	4.2849	0.023357	-0.0201	-0.012583	-0.005	0.0052928

Device Test: 82.2 UVLO BP5L Fall Thresh VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

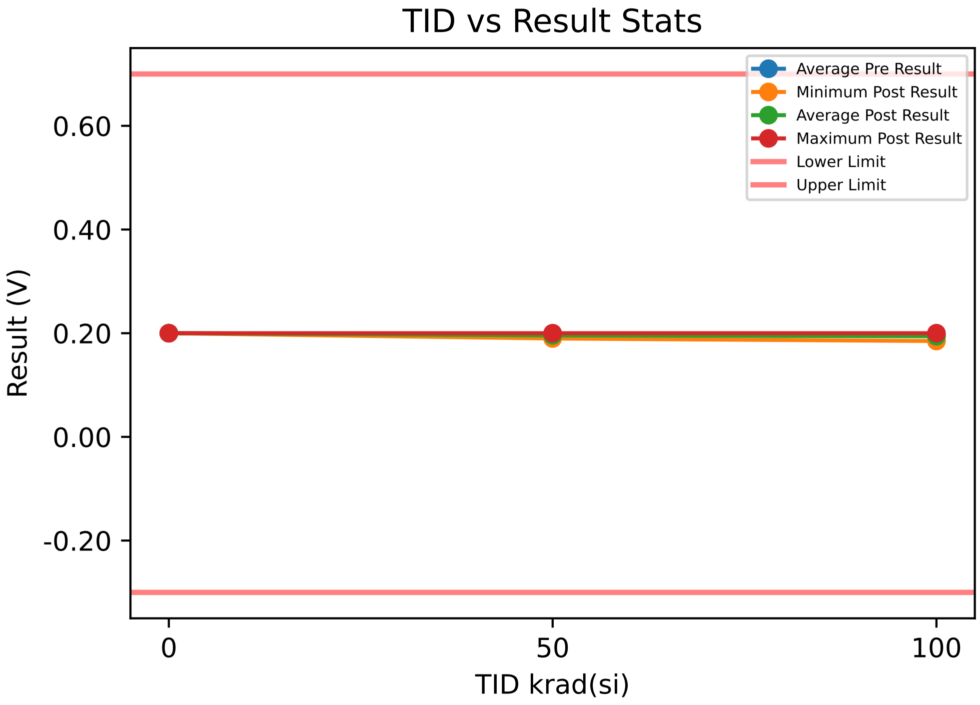
Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

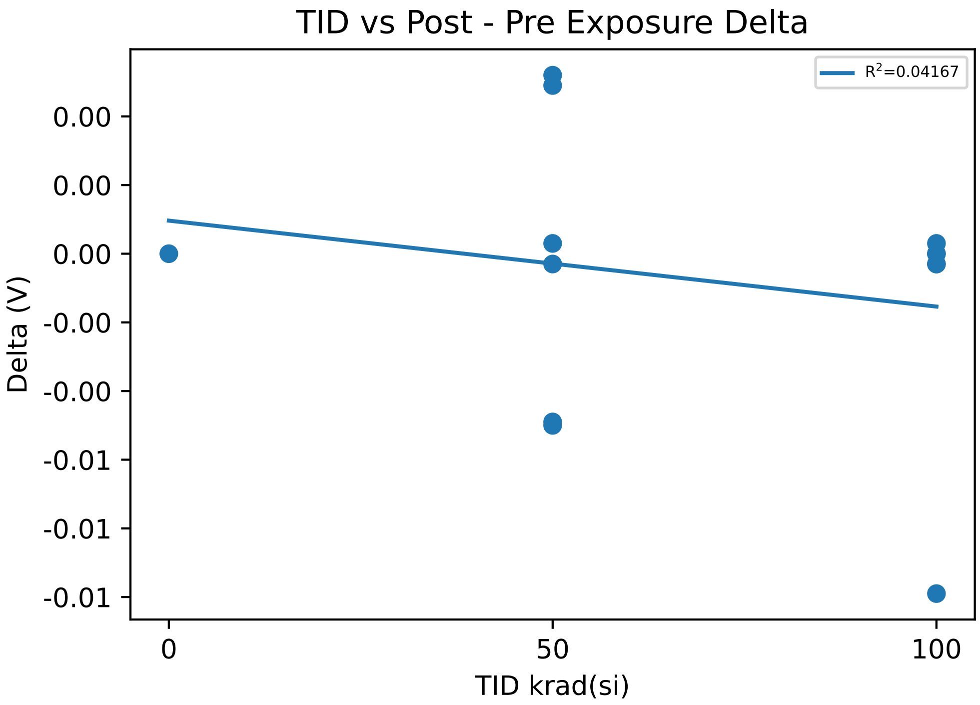
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.0651	4.0701	0.005
60	50	Biased	4.0701	4.0549	-0.0152
61	50	Biased	4.0701	4.0599	-0.0102
63	100	Biased	4.08	4.0651	-0.0149
64	100	Biased	4.075	4.0599	-0.0151
65	100	Biased	4.105	4.0849	-0.0201
66	50	Unbiased	4.075	4.075	0
67	50	Unbiased	4.075	4.0701	-0.0049
68	50	Unbiased	4.075	4.08	0.005
69	100	Unbiased	4.075	4.0651	-0.0099
70	100	Unbiased	4.0352	4.0249	-0.0103
71	100	Unbiased	4.0401	4.045	0.0049
72	0	Control	4.08	4.08	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.08	4.08	4.08		4.08	4.08	4.08		0	0	0	
50	4.0651	4.0717	4.075	0.0040336	4.0549	4.0683	4.08	0.0093635	-0.0152	-0.0033833	0.005	0.0082512
100	4.0352	4.0684	4.105	0.026322	4.0249	4.0575	4.0849	0.02045	-0.0201	-0.0109	0.0049	0.008594

Device Test: 82.3 UVLO BP5L Thresh Hysteresis VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

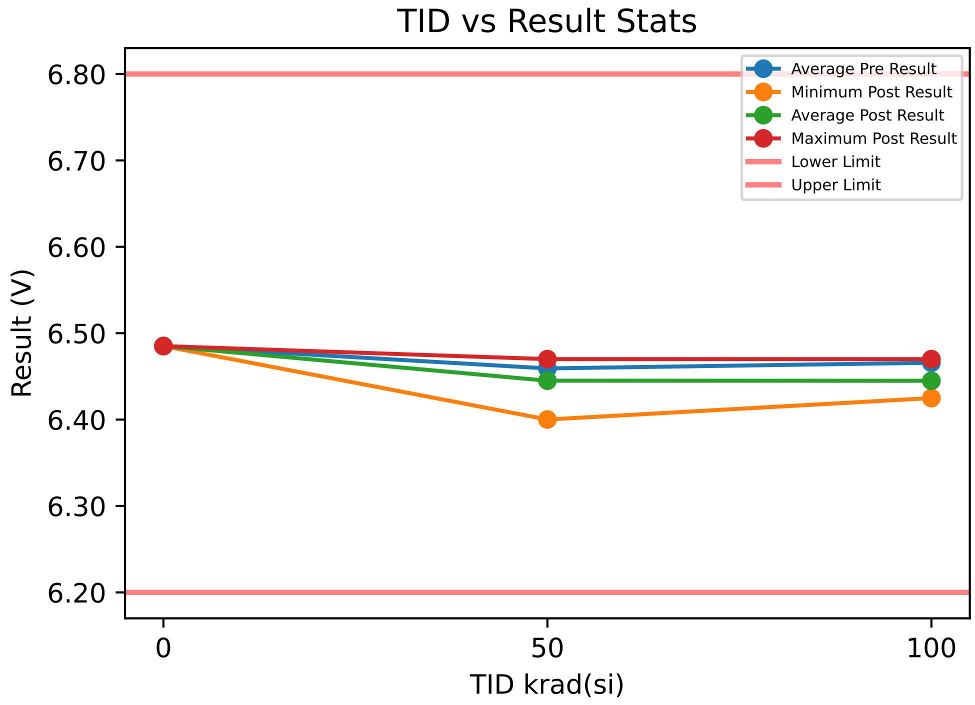
Test Results (Lower Limit = -0.3, Upper Limit = 0.7 (V))

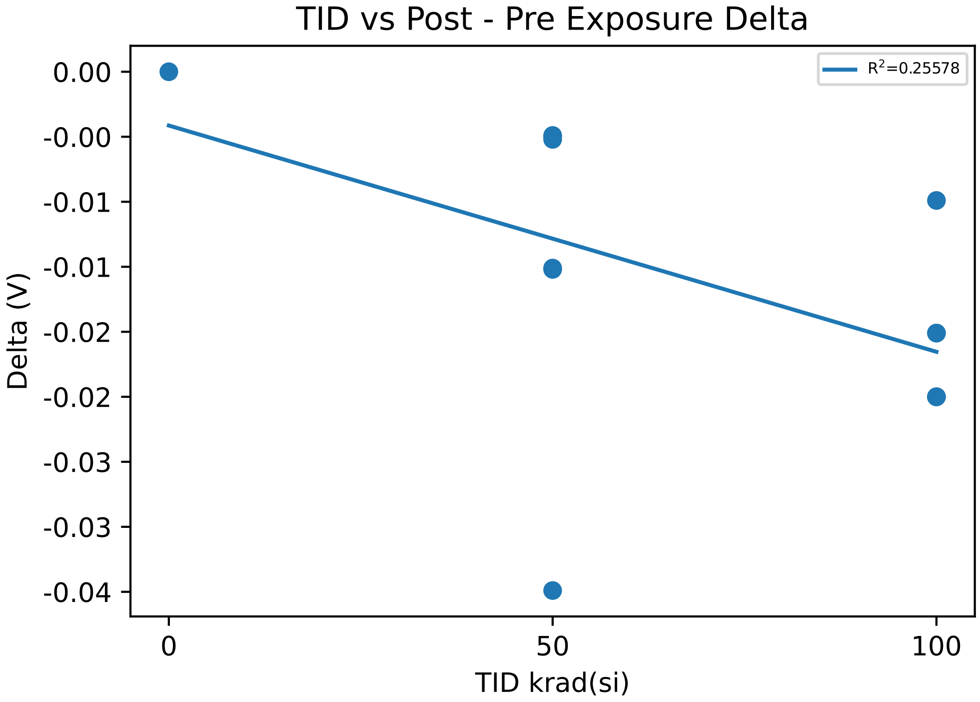
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.1948	0.1898	-0.005
60	50	Biased	0.1948	0.2	0.0052
61	50	Biased	0.1948	0.1951	0.0003
63	100	Biased	0.1951	0.1948	-0.0003
64	100	Biased	0.1951	0.1951	0
65	100	Biased	0.2	0.2	0
66	50	Unbiased	0.1951	0.2	0.0049
67	50	Unbiased	0.1951	0.1948	-0.0003
68	50	Unbiased	0.2	0.1951	-0.0049
69	100	Unbiased	0.1951	0.1948	-0.0003
70	100	Unbiased	0.1948	0.1951	0.0003
71	100	Unbiased	0.1948	0.1849	-0.0099
72	0	Control	0.2	0.2	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2	0.2	0.2		0.2	0.2	0.2		0	0	0	
50	0.1948	0.19577	0.2	0.0020791	0.1898	0.1958	0.2	0.0038278	-0.005	3.3333e-05	0.0052	0.0044774
100	0.1948	0.19582	0.2	0.0020547	0.1849	0.19412	0.2	0.0049483	-0.0099	-0.0017	0.0003	0.0040234

Device Test: 82.4 UVLO BP7L Rise Thresh VIN_14V





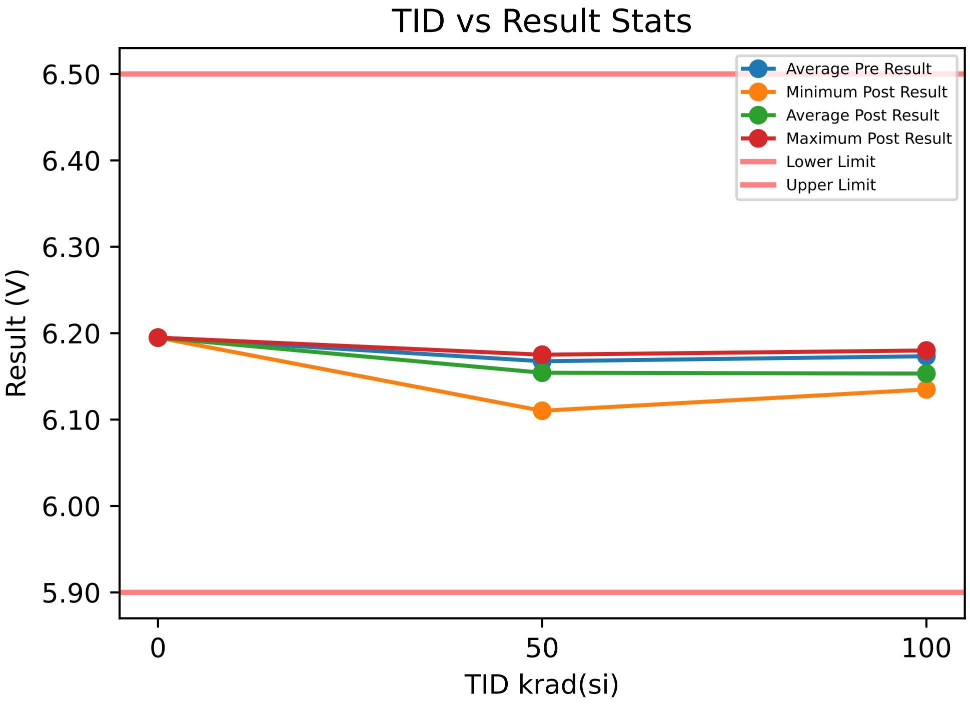
Test Results (Lower Limit = 6.2, Upper Limit = 6.8 (V))

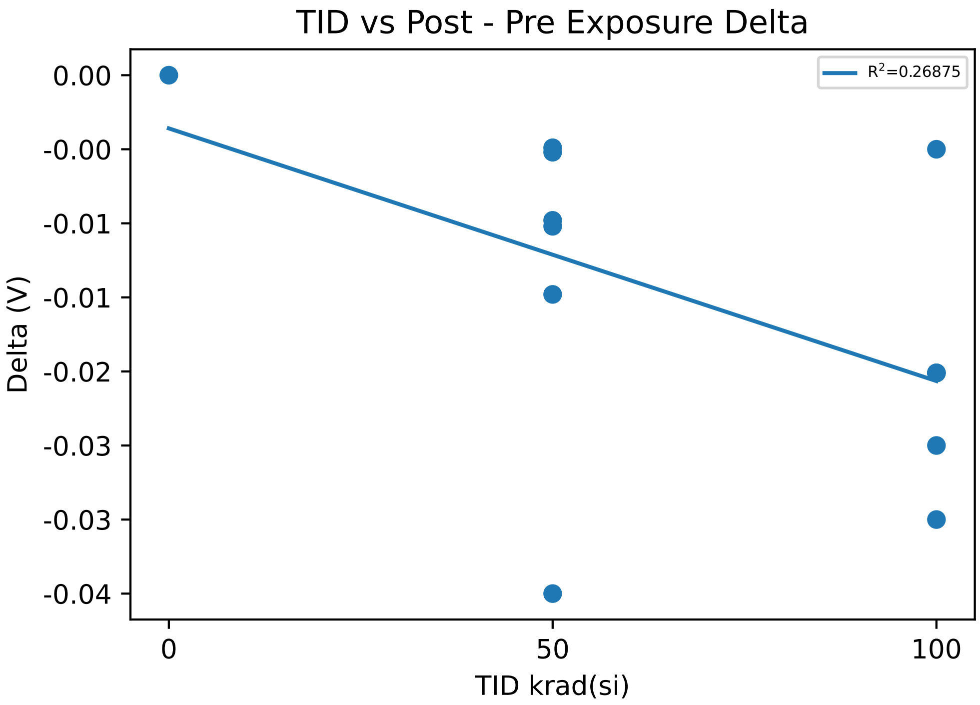
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.4051	6.4001	-0.005
60	50	Biased	6.47	6.4301	-0.0399
61	50	Biased	6.4851	6.47	-0.0151
63	100	Biased	6.4651	6.445	-0.0201
64	100	Biased	6.4799	6.4549	-0.025
65	100	Biased	6.4749	6.4499	-0.025
66	50	Unbiased	6.4651	6.4499	-0.0152
67	50	Unbiased	6.4601	6.4549	-0.0052
68	50	Unbiased	6.47	6.4651	-0.0049
69	100	Unbiased	6.4799	6.47	-0.0099
70	100	Unbiased	6.445	6.4249	-0.0201
71	100	Unbiased	6.4499	6.4249	-0.025
72	0	Control	6.4851	6.4851	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.4851	6.4851	6.4851		6.4851	6.4851	6.4851		0	0	0	
50	6.4051	6.4592	6.4851	0.027808	6.4001	6.445	6.47	0.026035	-0.0399	-0.014217	-0.0049	0.013524
100	6.445	6.4658	6.4799	0.015273	6.4249	6.4449	6.47	0.017635	-0.025	-0.02085	-0.0099	0.005877

Device Test: 82.5 UVLO BP7L Fall Thresh VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

Test Results (Lower Limit = 5.9, Upper Limit = 6.5 (V))

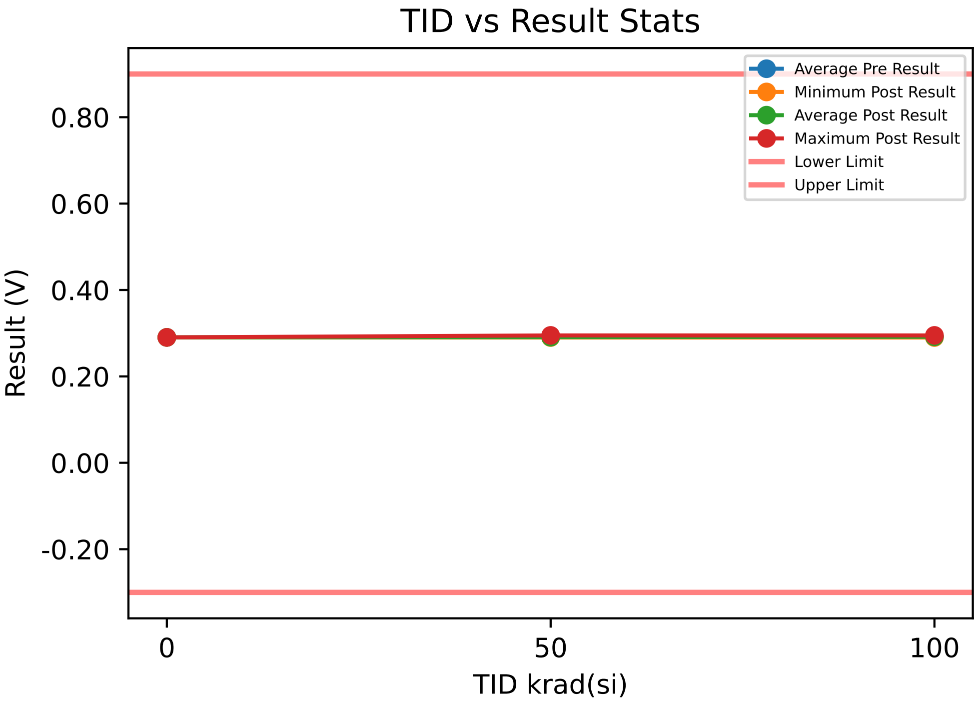
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	6.12	6.1102	-0.0098
60	50	Biased	6.1751	6.1401	-0.035
61	50	Biased	6.1899	6.1751	-0.0148
63	100	Biased	6.1701	6.15	-0.0201
64	100	Biased	6.185	6.1649	-0.0201
65	100	Biased	6.185	6.155	-0.03
66	50	Unbiased	6.1701	6.1599	-0.0102
67	50	Unbiased	6.1701	6.1649	-0.0052
68	50	Unbiased	6.18	6.1751	-0.0049
69	100	Unbiased	6.185	6.18	-0.005
70	100	Unbiased	6.155	6.1349	-0.0201
71	100	Unbiased	6.1599	6.1349	-0.025
72	0	Control	6.1949	6.1949	0

Test Statistics (V)

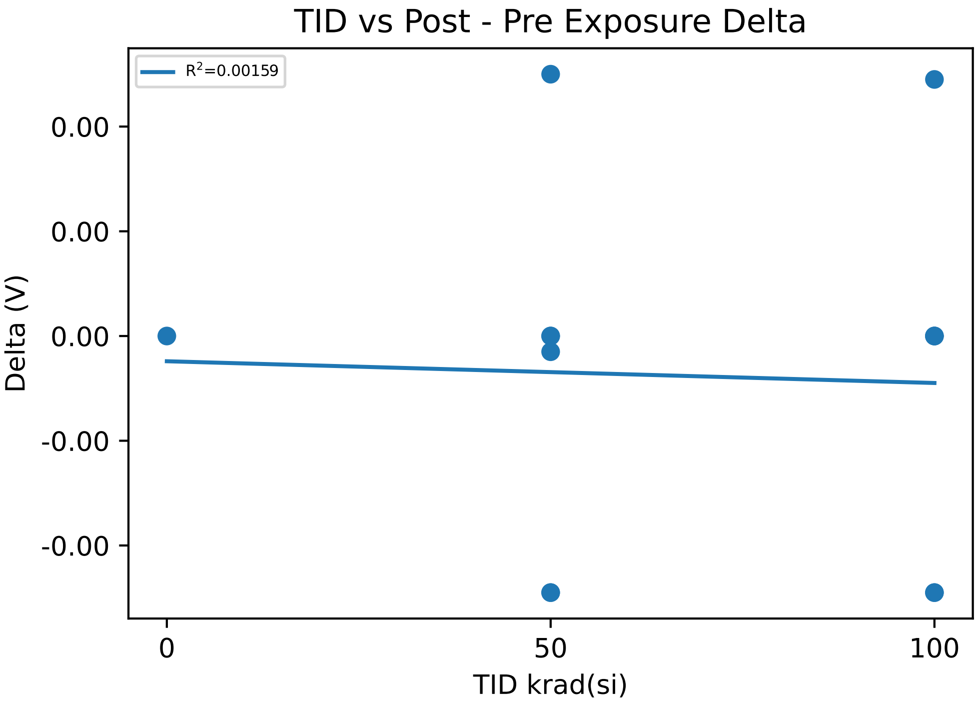
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.1949	6.1949	6.1949		6.1949	6.1949	6.1949		0	0	0	
50	6.12	6.1675	6.1899	0.024436	6.1102	6.1542	6.1751	0.025121	-0.035	-0.013317	-0.0049	0.011235
100	6.155	6.1733	6.185	0.013677	6.1349	6.1533	6.18	0.017541	-0.03	-0.02005	-0.005	0.0083668

Device Test: 82.6 UVLO BP7L Thresh Hysteresis VIN_14V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



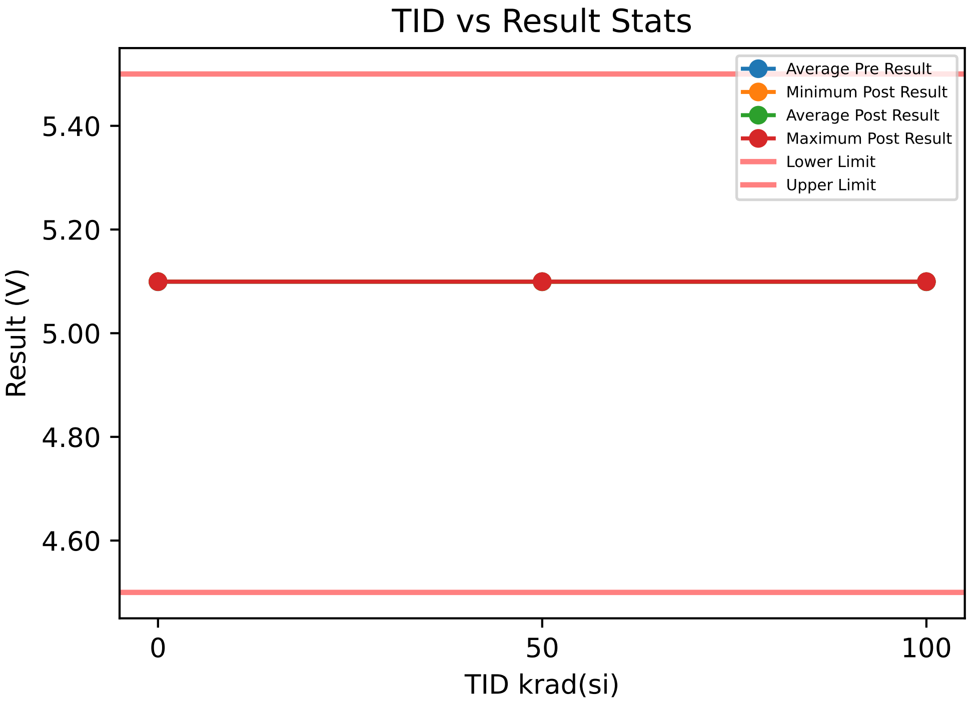
Test Results (Lower Limit = -0.3, Upper Limit = 0.9 (V))

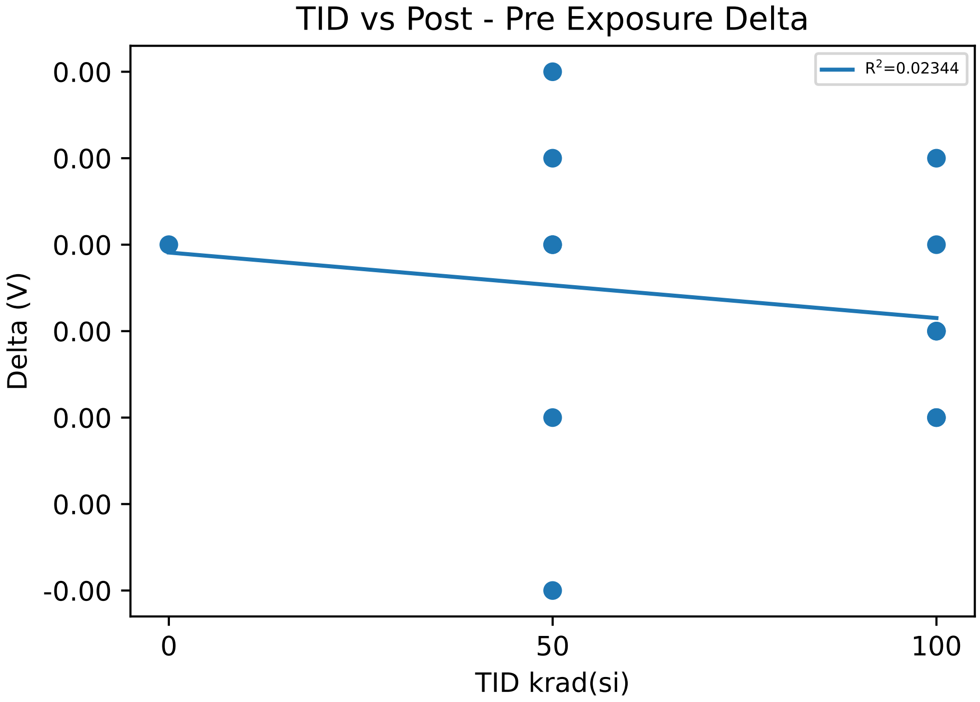
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.285	0.29	0.005
60	50	Biased	0.2949	0.29	-0.0049
61	50	Biased	0.2952	0.2949	-0.0003
63	100	Biased	0.2949	0.2949	0
64	100	Biased	0.2949	0.29	-0.0049
65	100	Biased	0.29	0.2949	0.0049
66	50	Unbiased	0.2949	0.29	-0.0049
67	50	Unbiased	0.29	0.29	0
68	50	Unbiased	0.29	0.29	0
69	100	Unbiased	0.2949	0.29	-0.0049
70	100	Unbiased	0.29	0.29	0
71	100	Unbiased	0.29	0.29	0
72	0	Control	0.2903	0.2903	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2903	0.2903	0.2903		0.2903	0.2903	0.2903		0	0	0	
50	0.285	0.29167	0.2952	0.004084	0.29	0.29082	0.2949	0.0020004	-0.0049	-0.00085	0.005	0.0037088
100	0.29	0.29245	0.2949	0.0026838	0.29	0.29163	0.2949	0.0025303	-0.0049	-0.00081667	0.0049	0.0036886

Device Test: 85.0 TM1 - HMUX V VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

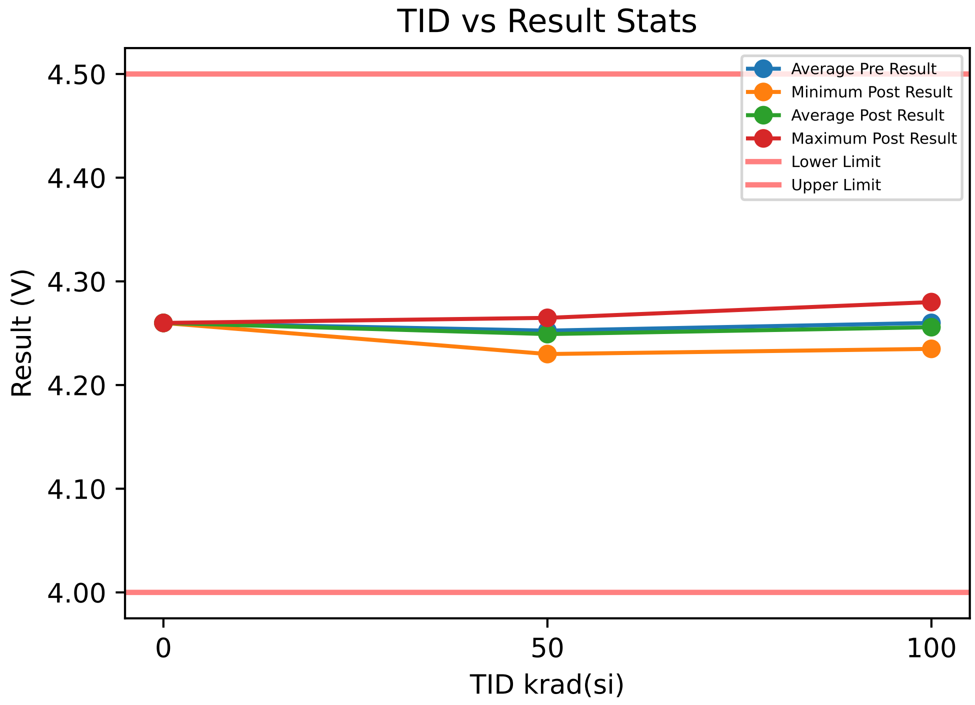
Test Results (Lower Limit = 4.5, Upper Limit = 5.5 (V))

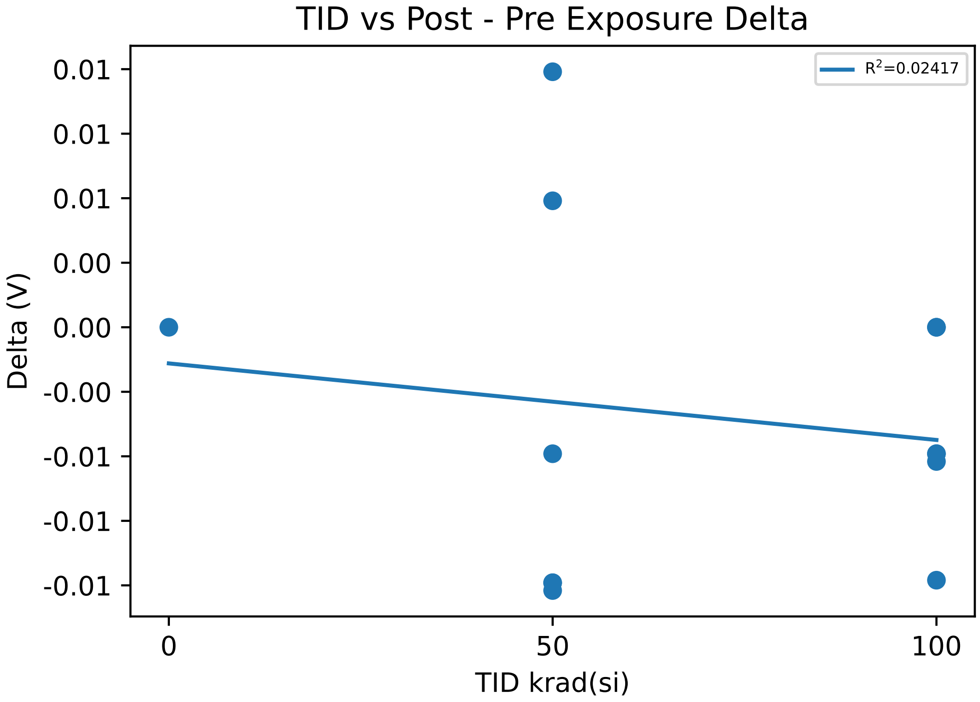
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0994	5.0995	0.0001
60	50	Biased	5.0992	5.0995	0.0003
61	50	Biased	5.099	5.0995	0.0005
63	100	Biased	5.0993	5.0994	0.0001
64	100	Biased	5.0991	5.0995	0.0004
65	100	Biased	5.0992	5.0995	0.0003
66	50	Unbiased	5.099	5.0994	0.0004
67	50	Unbiased	5.0993	5.0992	-0.0001
68	50	Unbiased	5.0991	5.0994	0.0003
69	100	Unbiased	5.0992	5.0993	0.0001
70	100	Unbiased	5.0991	5.0993	0.0002
71	100	Unbiased	5.0992	5.0994	0.0002
72	0	Control	5.0992	5.0995	0.0003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0992	5.0992	5.0992		5.0995	5.0995	5.0995		0.0003	0.0003	0.0003	
50	5.099	5.0992	5.0994	0.0001633	5.0992	5.0994	5.0995	0.0001169	-0.0001	0.00025	0.0005	0.00021679
100	5.0991	5.0992	5.0993	7.5277e-05	5.0993	5.0994	5.0995	8.9443e-05	0.0001	0.00021667	0.0004	0.0001169

Device Test: 85.1 UVLO BP5H Rise Thresh VIN_10V





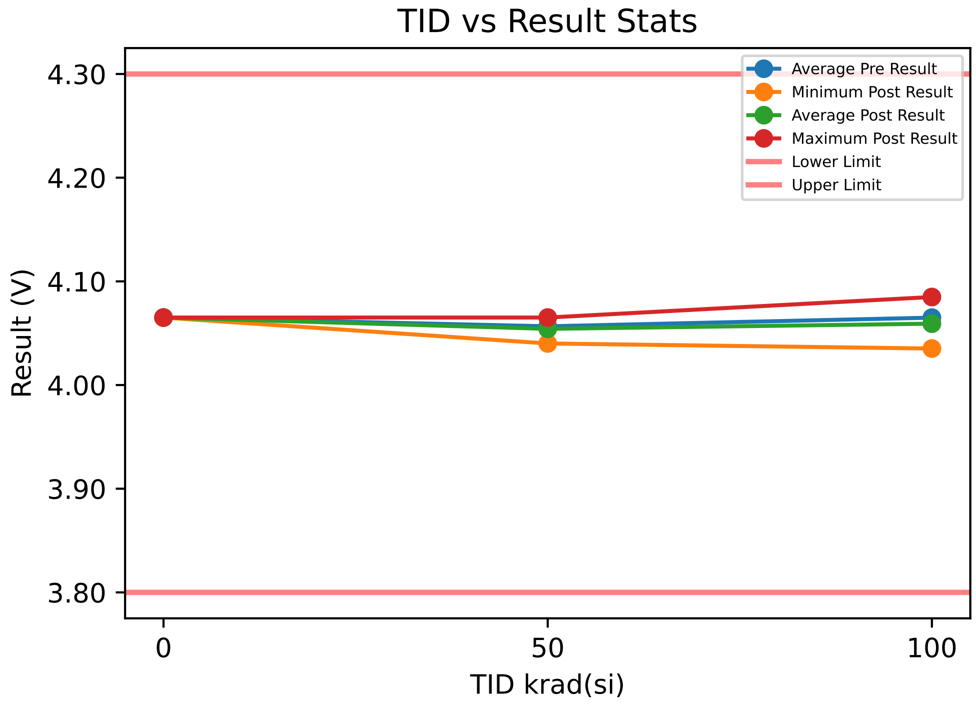
Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

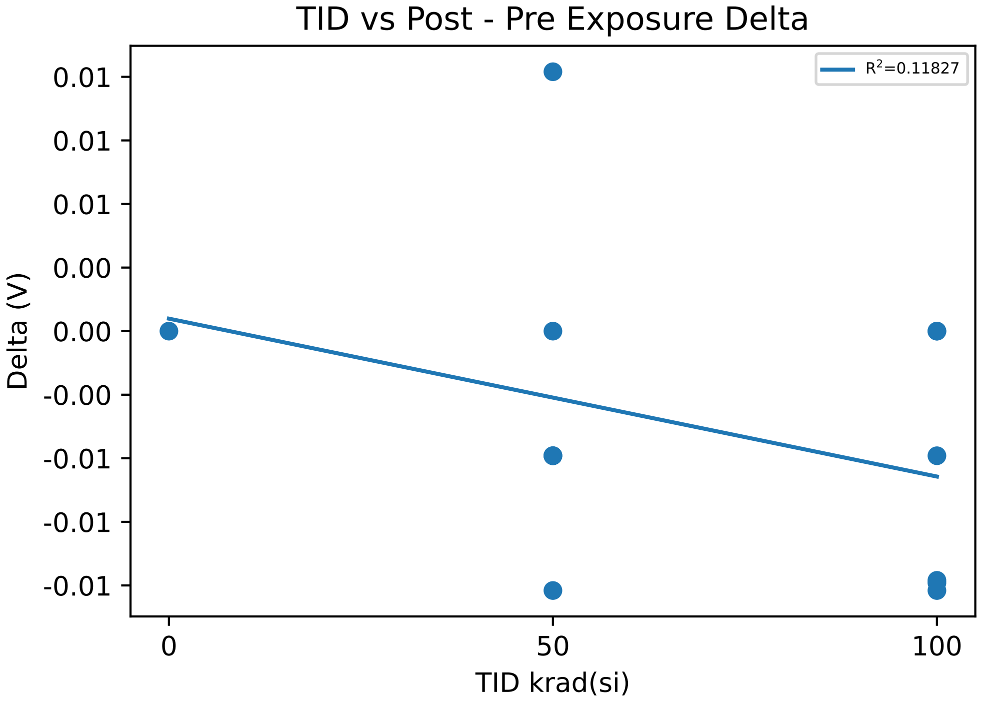
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.255	4.2451	-0.0099
60	50	Biased	4.2401	4.2299	-0.0102
61	50	Biased	4.25	4.2451	-0.0049
63	100	Biased	4.28	4.28	0
64	100	Biased	4.2401	4.2349	-0.0052
65	100	Biased	4.25	4.2451	-0.0049
66	50	Unbiased	4.2599	4.2648	0.0049
67	50	Unbiased	4.2599	4.25	-0.0099
68	50	Unbiased	4.25	4.2599	0.0099
69	100	Unbiased	4.2648	4.255	-0.0098
70	100	Unbiased	4.2648	4.2599	-0.0049
71	100	Unbiased	4.2599	4.2599	0
72	0	Control	4.2599	4.2599	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.2599	4.2599	4.2599		4.2599	4.2599	4.2599		0	0	0	
50	4.2401	4.2525	4.2599	0.0075104	4.2299	4.2491	4.2648	0.012366	-0.0102	-0.00335	0.0099	0.0087035
100	4.2401	4.2599	4.28	0.013726	4.2349	4.2558	4.28	0.015305	-0.0098	-0.0041333	0	0.0037039

Device Test: 85.2 UVLO BP5H Fall Thresh VIN_10V





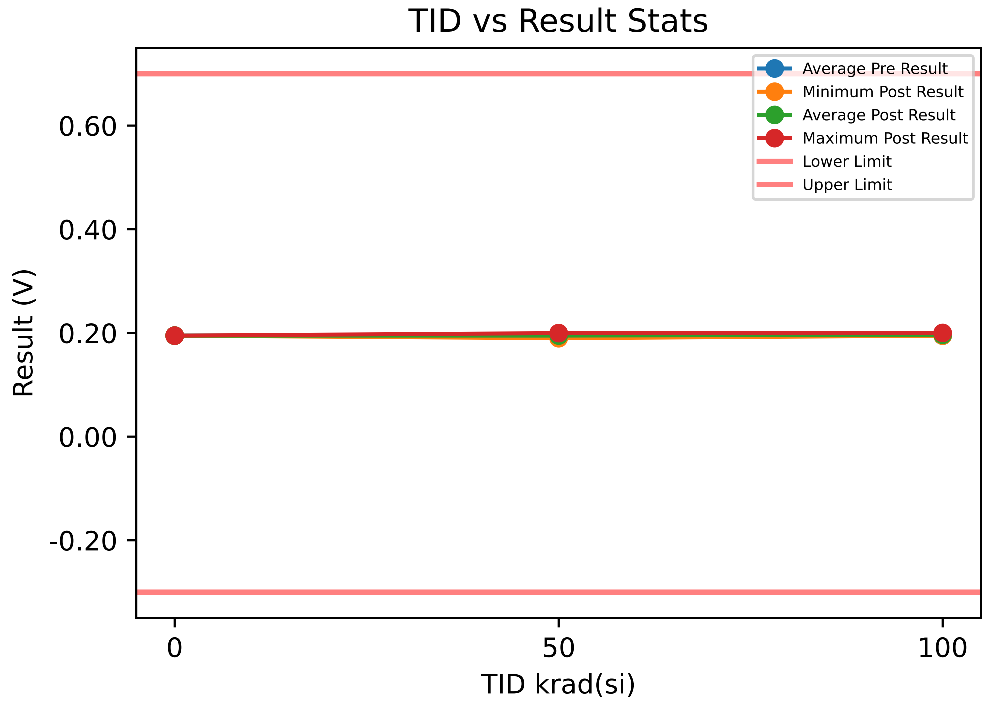
Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

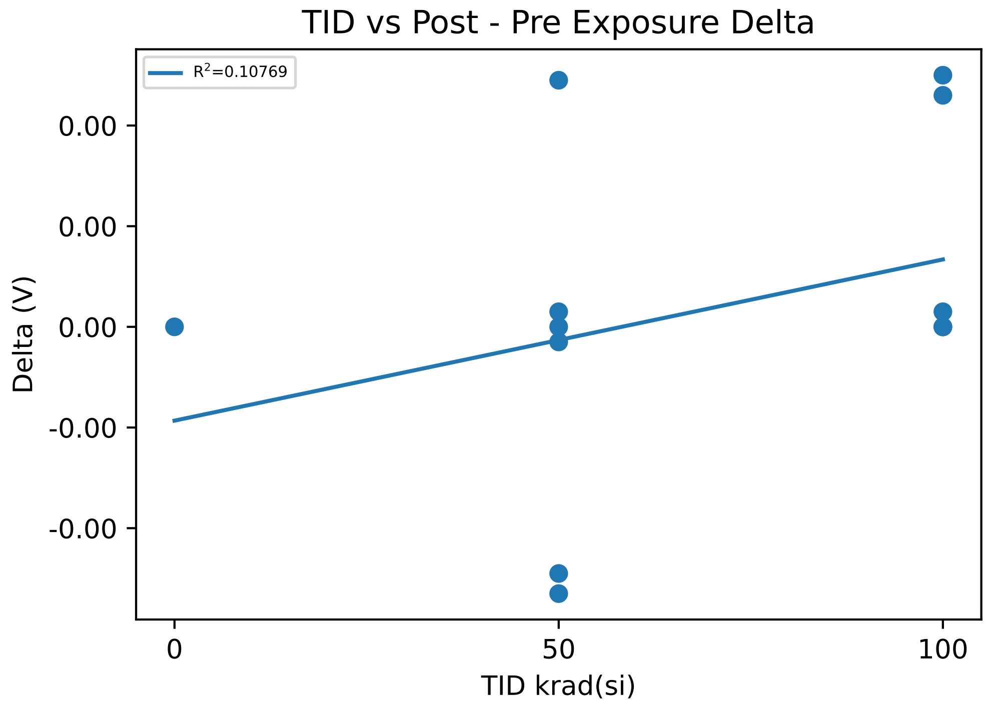
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.0549	4.05	-0.0049
60	50	Biased	4.045	4.0401	-0.0049
61	50	Biased	4.0549	4.05	-0.0049
63	100	Biased	4.0849	4.0849	0
64	100	Biased	4.045	4.0352	-0.0098
65	100	Biased	4.0549	4.05	-0.0049
66	50	Unbiased	4.0651	4.0651	0
67	50	Unbiased	4.0651	4.0549	-0.0102
68	50	Unbiased	4.0549	4.0651	0.0102
69	100	Unbiased	4.0651	4.0549	-0.0102
70	100	Unbiased	4.075	4.0651	-0.0099
71	100	Unbiased	4.0651	4.0651	0
72	0	Control	4.0651	4.0651	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0651	4.0651	4.0651		4.0651	4.0651	4.0651		0	0	0	
50	4.045	4.0567	4.0651	0.0075857	4.0401	4.0542	4.0651	0.009718	-0.0102	-0.00245	0.0102	0.0069871
100	4.045	4.065	4.0849	0.014128	4.0352	4.0592	4.0849	0.016788	-0.0102	-0.0058	0	0.0049043

Device Test: 85.3 UVLO BP5H Thresh Hysteresis VIN_10V





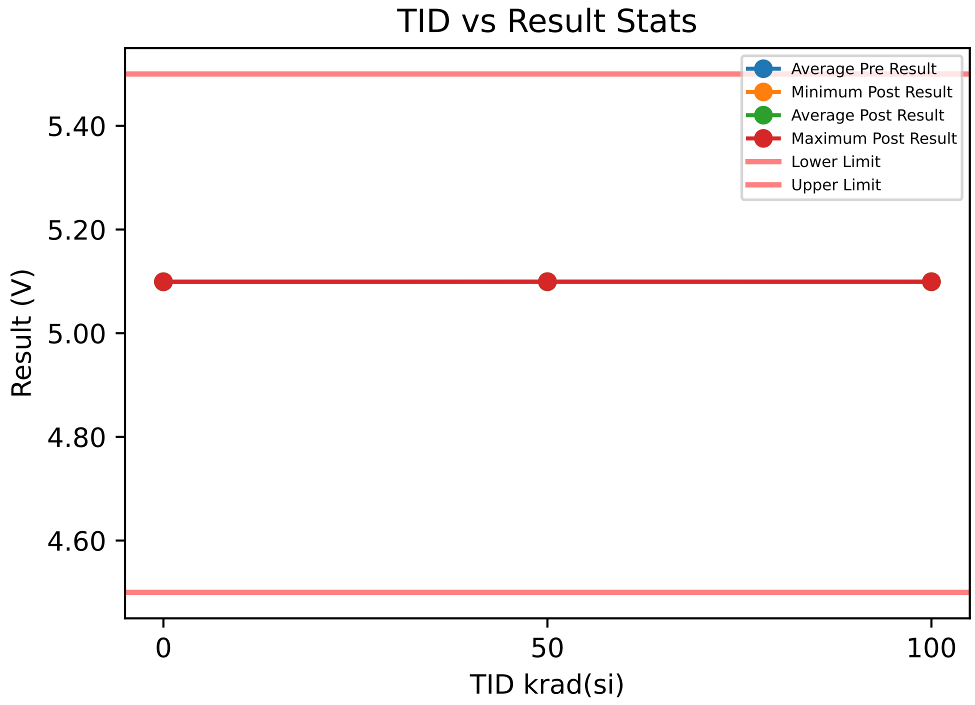
Test Results (Lower Limit = -0.3, Upper Limit = 0.7 (V))

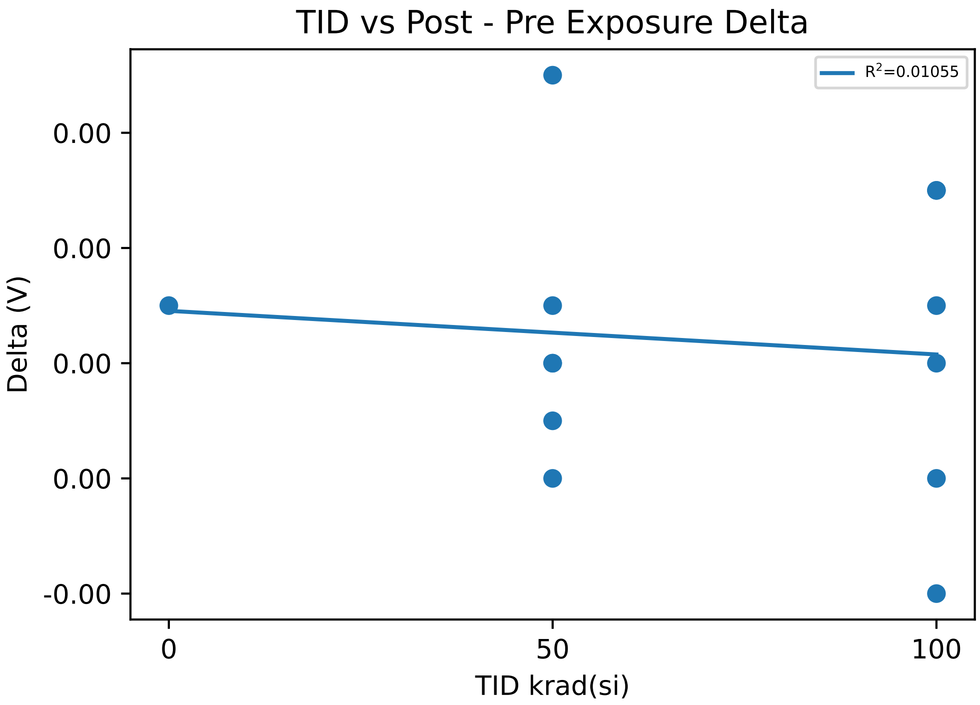
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.2	0.1951	-0.0049
60	50	Biased	0.1951	0.1898	-0.0053
61	50	Biased	0.1951	0.1951	0
63	100	Biased	0.1951	0.1951	0
64	100	Biased	0.1951	0.1997	0.0046
65	100	Biased	0.1951	0.1951	0
66	50	Unbiased	0.1948	0.1997	0.0049
67	50	Unbiased	0.1948	0.1951	0.0003
68	50	Unbiased	0.1951	0.1948	-0.0003
69	100	Unbiased	0.1997	0.2	0.0003
70	100	Unbiased	0.1898	0.1948	0.005
71	100	Unbiased	0.1948	0.1948	0
72	0	Control	0.1948	0.1948	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1948	0.1948	0.1948		0.1948	0.1948	0.1948		0	0	0	
50	0.1948	0.19582	0.2	0.0020547	0.1898	0.19493	0.1997	0.003136	-0.0053	-0.00088333	0.0049	0.0037844
100	0.1898	0.19493	0.1997	0.003136	0.1948	0.19658	0.2	0.0025357	0	0.00165	0.005	0.002446

Device Test: 86.0 TM1 - HMUX V VIN_12V





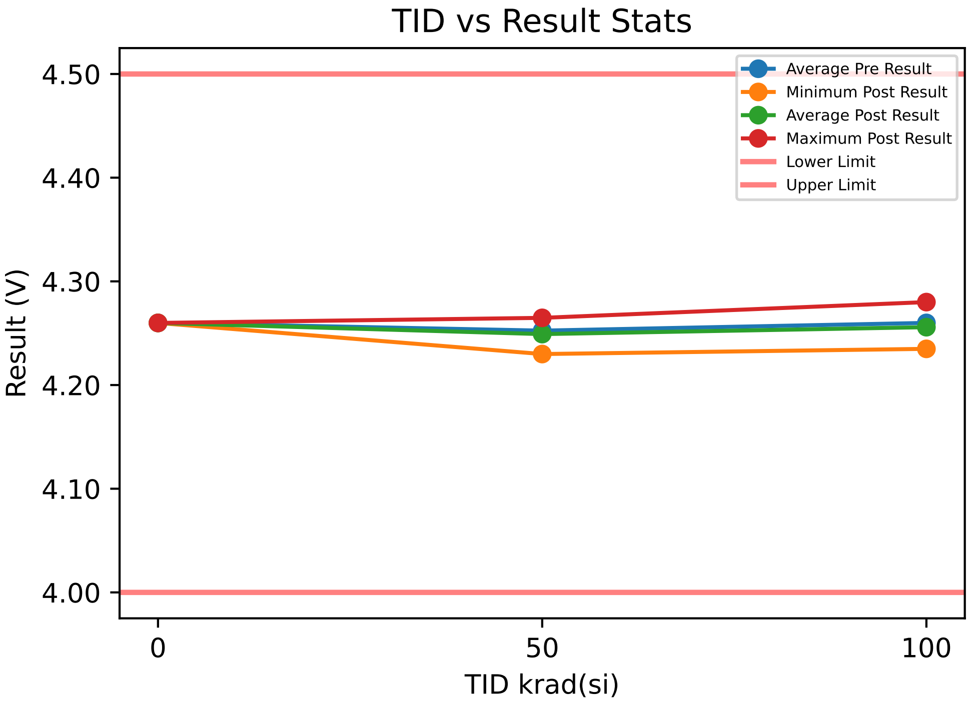
Test Results (Lower Limit = 4.5, Upper Limit = 5.5 (V))

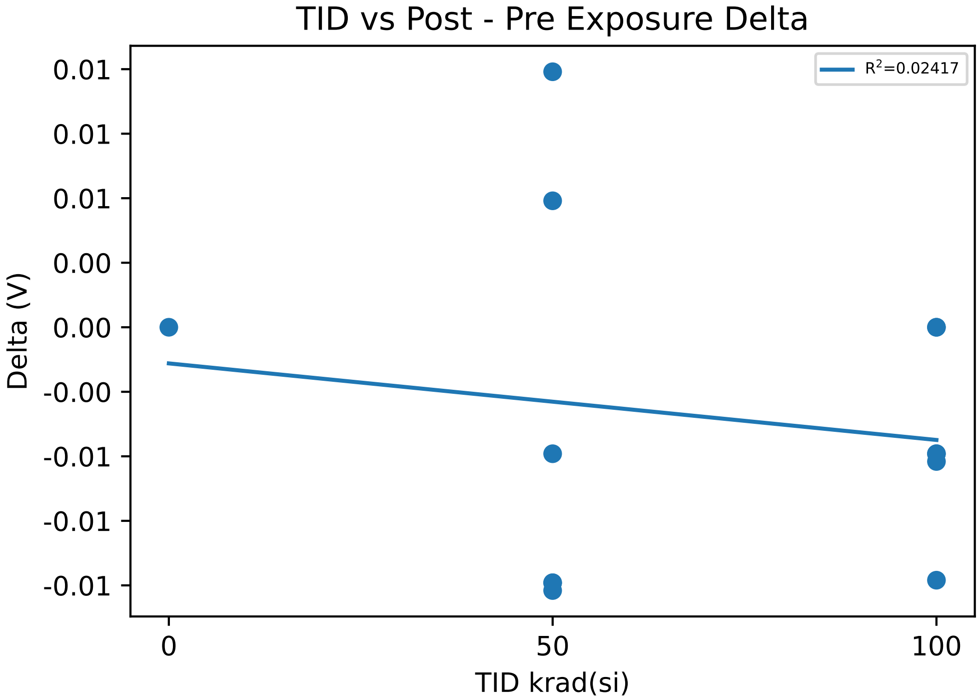
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0992	5.0993	0.0001
60	50	Biased	5.099	5.0992	0.0002
61	50	Biased	5.0993	5.0993	0
63	100	Biased	5.0992	5.0994	0.0002
64	100	Biased	5.0989	5.0994	0.0005
65	100	Biased	5.0991	5.0994	0.0003
66	50	Unbiased	5.0991	5.0994	0.0003
67	50	Unbiased	5.0991	5.0993	0.0002
68	50	Unbiased	5.0988	5.0995	0.0007
69	100	Unbiased	5.0994	5.0992	-0.0002
70	100	Unbiased	5.0989	5.0994	0.0005
71	100	Unbiased	5.0992	5.0992	0
72	0	Control	5.099	5.0993	0.0003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.099	5.099	5.099		5.0993	5.0993	5.0993		0.0003	0.0003	0.0003	
50	5.0988	5.0991	5.0993	0.00017224	5.0992	5.0993	5.0995	0.00010328	0	0.00025	0.0007	0.0002429
100	5.0989	5.0991	5.0994	0.00019408	5.0992	5.0993	5.0994	0.00010328	-0.0002	0.00021667	0.0005	0.00027869

Device Test: 86.1 UVLO BP5H Rise Thresh VIN_12V





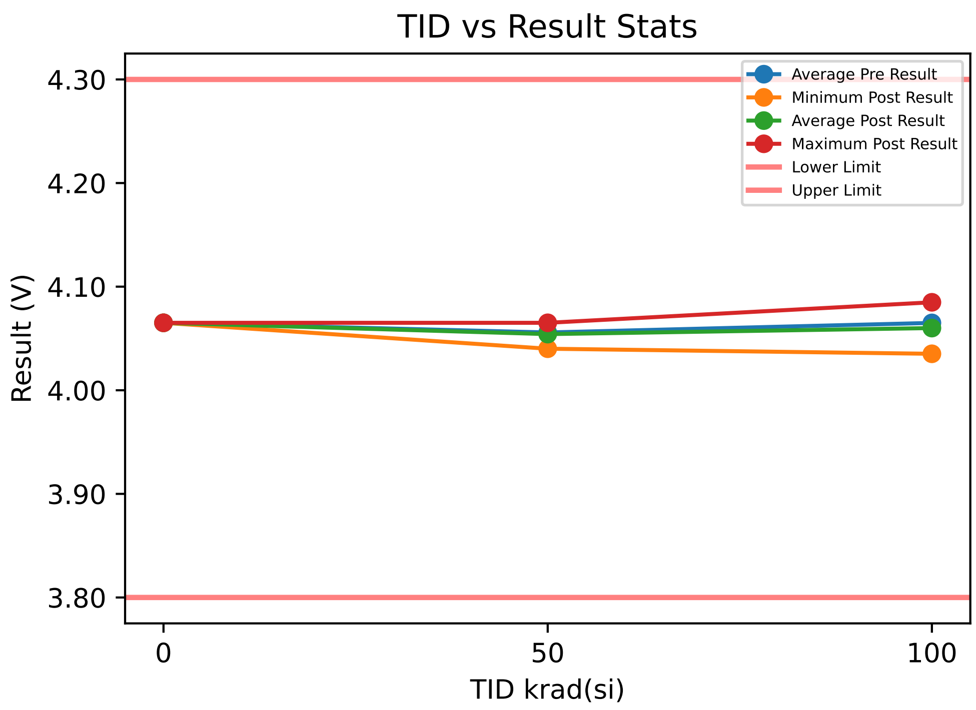
Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

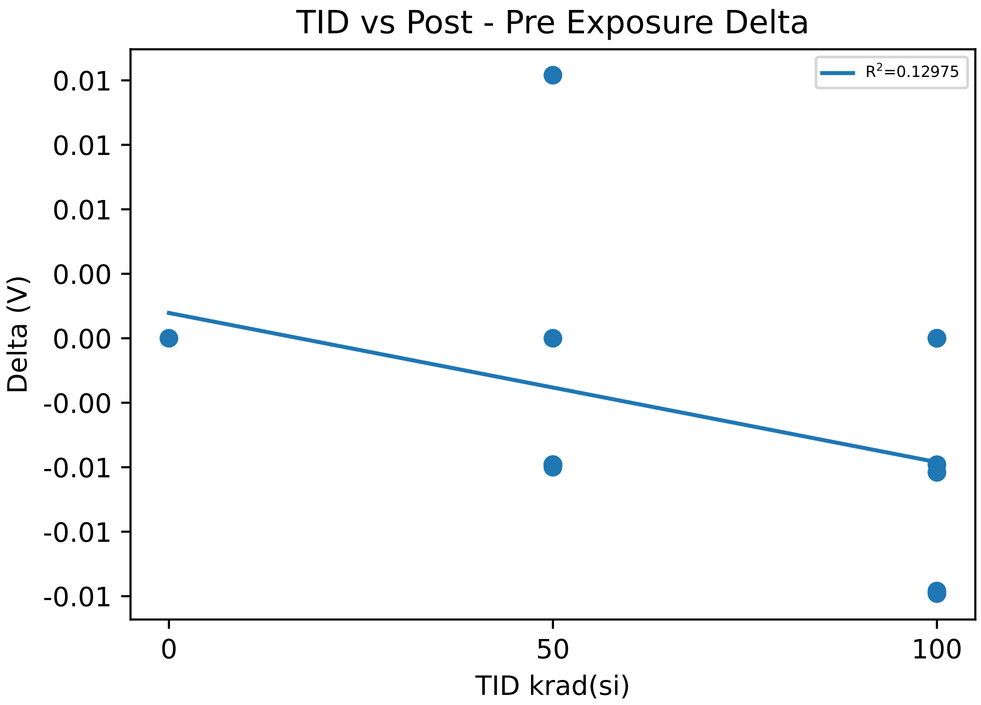
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.255	4.2451	-0.0099
60	50	Biased	4.2401	4.2299	-0.0102
61	50	Biased	4.25	4.2451	-0.0049
63	100	Biased	4.28	4.28	0
64	100	Biased	4.2401	4.2349	-0.0052
65	100	Biased	4.25	4.2451	-0.0049
66	50	Unbiased	4.2599	4.2648	0.0049
67	50	Unbiased	4.2599	4.25	-0.0099
68	50	Unbiased	4.25	4.2599	0.0099
69	100	Unbiased	4.2648	4.255	-0.0098
70	100	Unbiased	4.2648	4.2599	-0.0049
71	100	Unbiased	4.2599	4.2599	0
72	0	Control	4.2599	4.2599	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.2599	4.2599	4.2599		4.2599	4.2599	4.2599		0	0	0	
50	4.2401	4.2525	4.2599	0.0075104	4.2299	4.2491	4.2648	0.012366	-0.0102	-0.00335	0.0099	0.0087035
100	4.2401	4.2599	4.28	0.013726	4.2349	4.2558	4.28	0.015305	-0.0098	-0.0041333	0	0.0037039

Device Test: 86.2 UVLO BP5H Fall Thresh VIN_12V





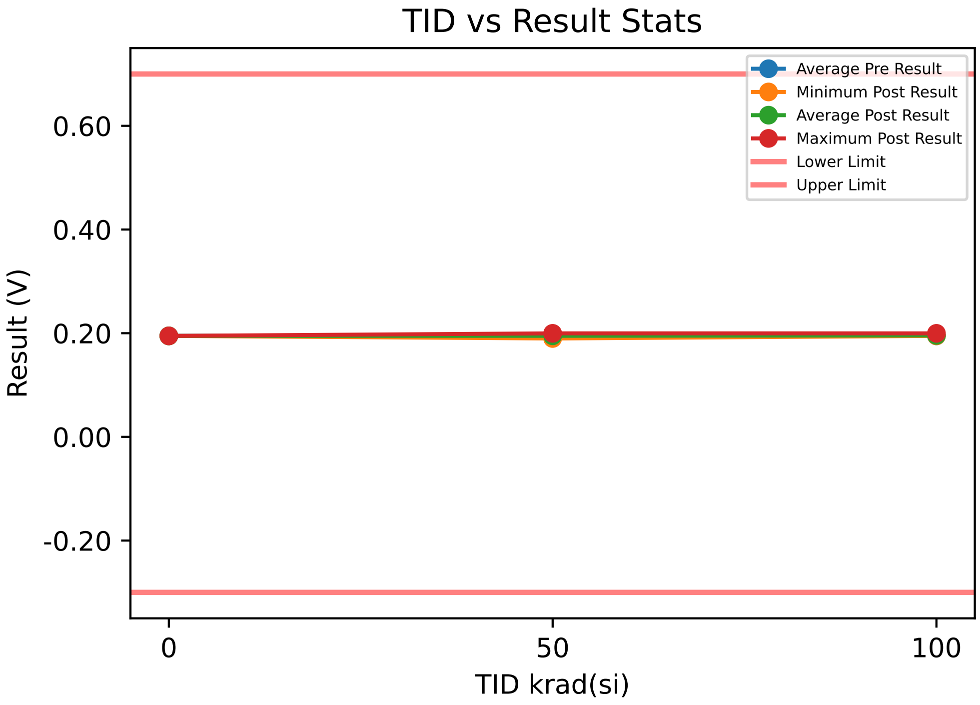
Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

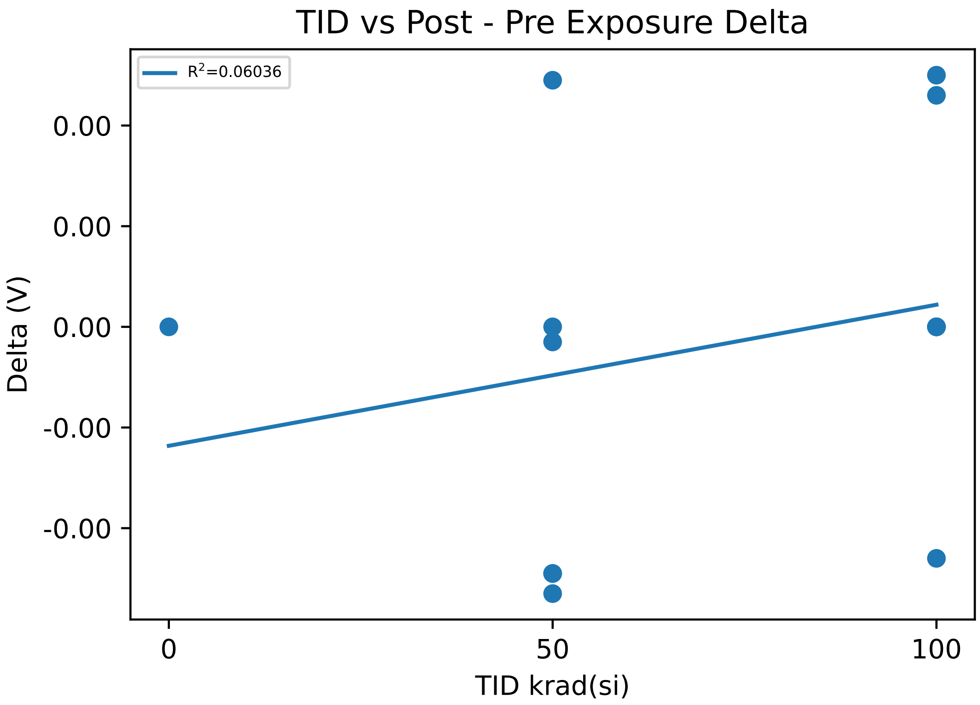
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.0549	4.05	-0.0049
60	50	Biased	4.045	4.0401	-0.0049
61	50	Biased	4.0549	4.05	-0.0049
63	100	Biased	4.0849	4.0849	0
64	100	Biased	4.045	4.0352	-0.0098
65	100	Biased	4.0549	4.05	-0.0049
66	50	Unbiased	4.0651	4.0651	0
67	50	Unbiased	4.0599	4.0549	-0.005
68	50	Unbiased	4.0549	4.0651	0.0102
69	100	Unbiased	4.0651	4.0599	-0.0052
70	100	Unbiased	4.075	4.0651	-0.0099
71	100	Unbiased	4.0651	4.0651	0
72	0	Control	4.0651	4.0651	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0651	4.0651	4.0651		4.0651	4.0651	4.0651		0	0	0	
50	4.045	4.0558	4.0651	0.0066689	4.0401	4.0542	4.0651	0.009718	-0.005	-0.0015833	0.0102	0.0060996
100	4.045	4.065	4.0849	0.014128	4.0352	4.06	4.0849	0.016656	-0.0099	-0.0049667	0	0.0044067

Device Test: 86.3 UVLO BP5H Thresh Hysteresis VIN_12V





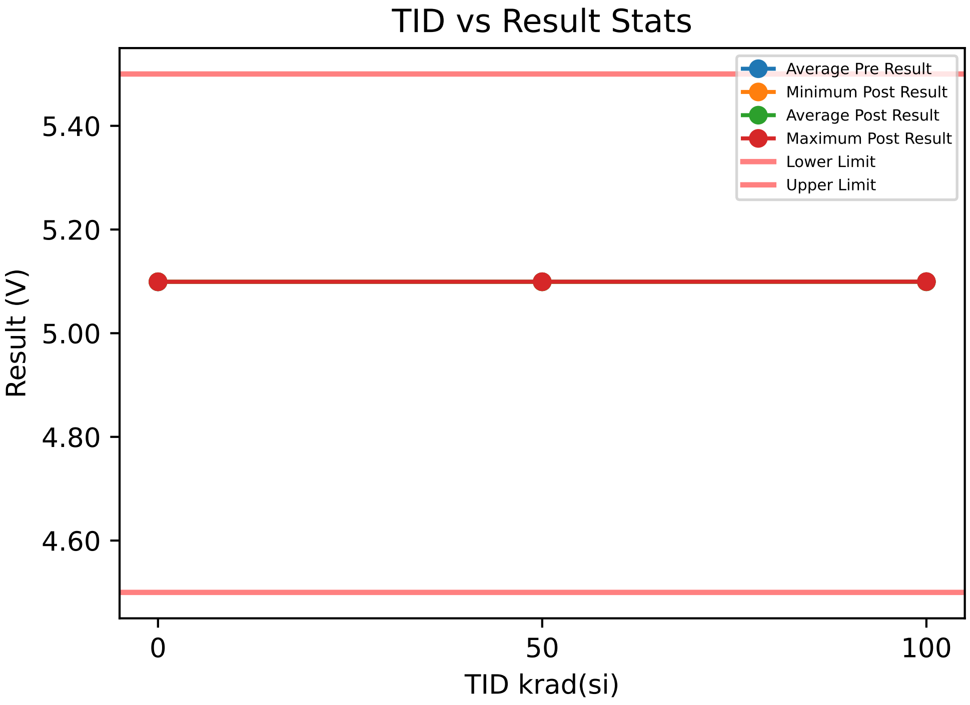
Test Results (Lower Limit = -0.3, Upper Limit = 0.7 (V))

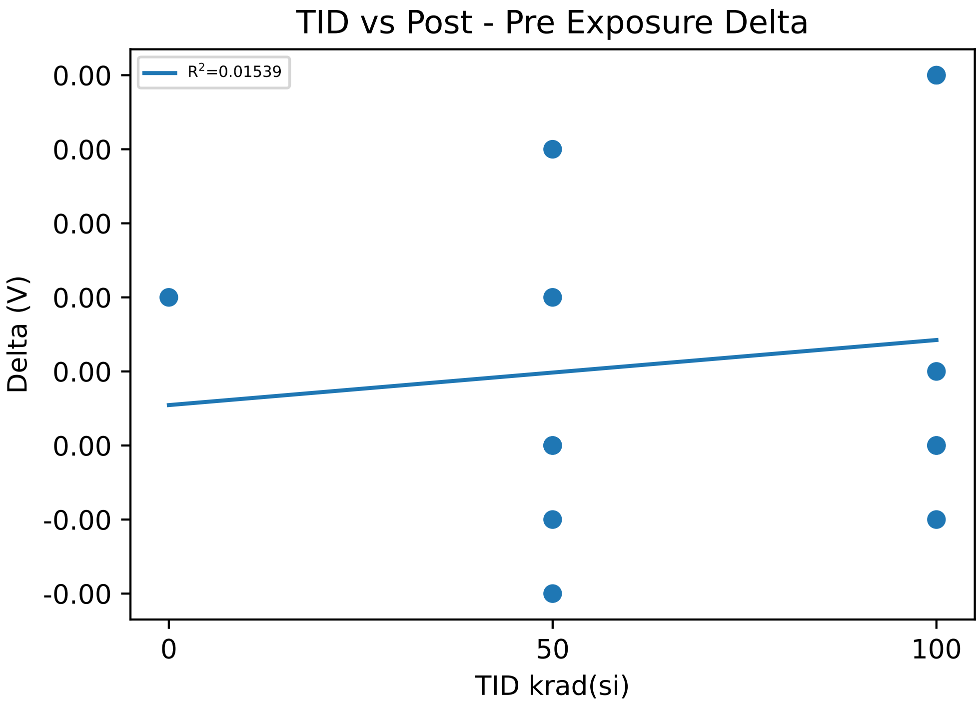
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.2	0.1951	-0.0049
60	50	Biased	0.1951	0.1898	-0.0053
61	50	Biased	0.1951	0.1951	0
63	100	Biased	0.1951	0.1951	0
64	100	Biased	0.1951	0.1997	0.0046
65	100	Biased	0.1951	0.1951	0
66	50	Unbiased	0.1948	0.1997	0.0049
67	50	Unbiased	0.2	0.1951	-0.0049
68	50	Unbiased	0.1951	0.1948	-0.0003
69	100	Unbiased	0.1997	0.1951	-0.0046
70	100	Unbiased	0.1898	0.1948	0.005
71	100	Unbiased	0.1948	0.1948	0
72	0	Control	0.1948	0.1948	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1948	0.1948	0.1948		0.1948	0.1948	0.1948		0	0	0	
50	0.1948	0.19668	0.2	0.0025717	0.1898	0.19493	0.1997	0.003136	-0.0053	-0.00175	0.0049	0.0040456
100	0.1898	0.19493	0.1997	0.003136	0.1948	0.19577	0.1997	0.0019325	-0.0046	0.00083333	0.005	0.003554

Device Test: 87.0 TM1 - HMUX V VIN_14V





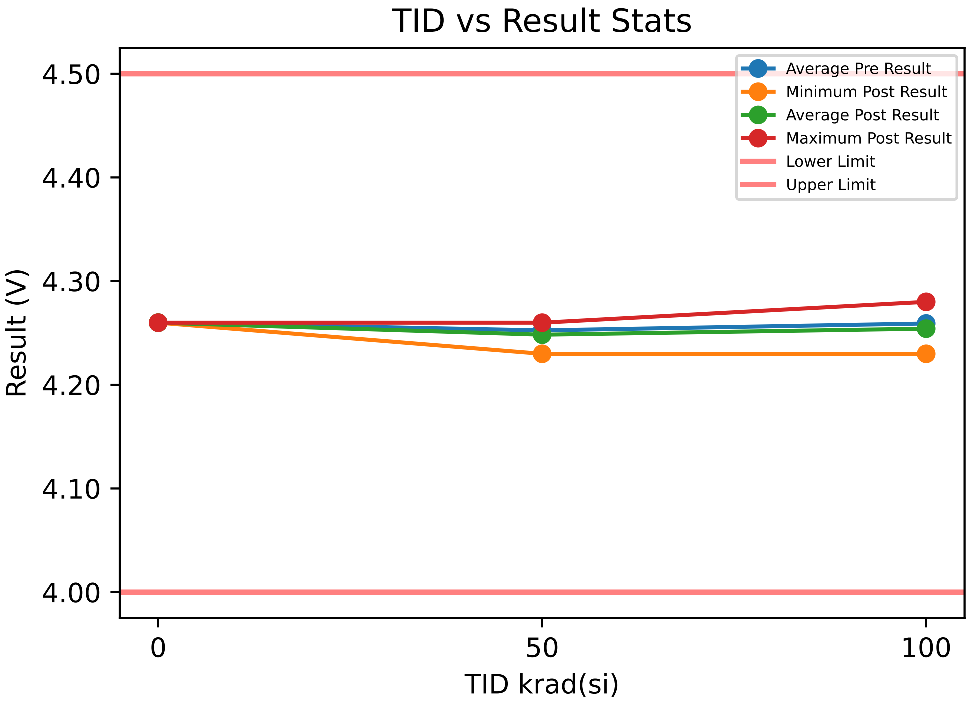
Test Results (Lower Limit = 4.5, Upper Limit = 5.5 (V))

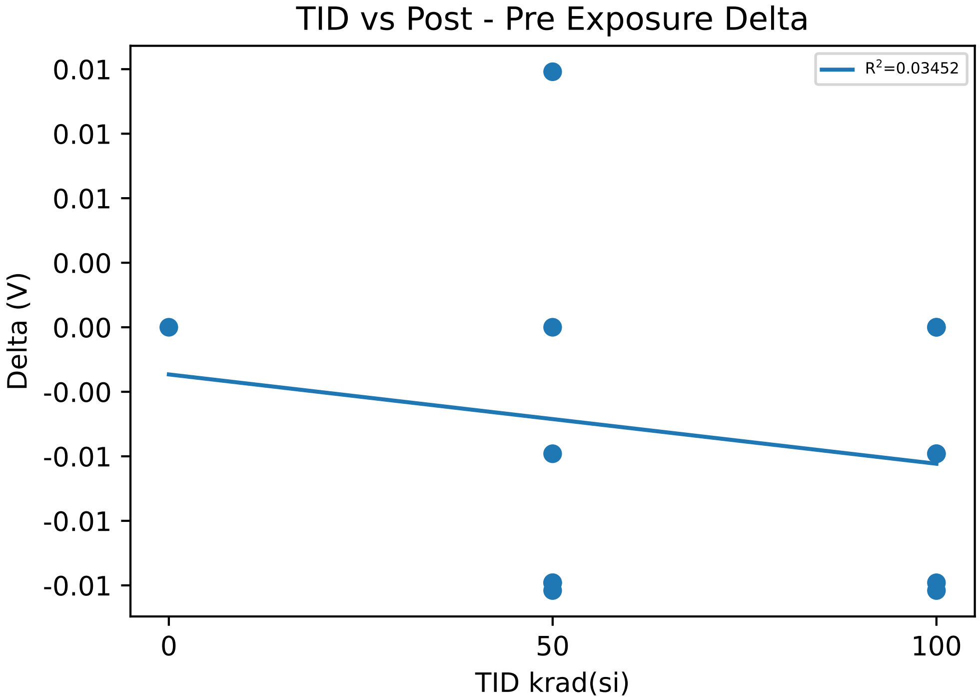
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	5.0992	5.0992	0
60	50	Biased	5.0991	5.0991	0
61	50	Biased	5.0993	5.0991	-0.0002
63	100	Biased	5.0992	5.0993	0.0001
64	100	Biased	5.099	5.0995	0.0005
65	100	Biased	5.0994	5.0993	-0.0001
66	50	Unbiased	5.099	5.0992	0.0002
67	50	Unbiased	5.0994	5.0993	-0.0001
68	50	Unbiased	5.0989	5.0993	0.0004
69	100	Unbiased	5.0992	5.0992	0
70	100	Unbiased	5.0989	5.0994	0.0005
71	100	Unbiased	5.0993	5.0993	0
72	0	Control	5.099	5.0992	0.0002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.099	5.099	5.099		5.0992	5.0992	5.0992		0.0002	0.0002	0.0002	
50	5.0989	5.0992	5.0994	0.00018708	5.0991	5.0992	5.0993	8.9443e-05	-0.0002	5e-05	0.0004	0.00021679
100	5.0989	5.0992	5.0994	0.00018619	5.0992	5.0993	5.0995	0.00010328	-0.0001	0.00016667	0.0005	0.00026583

Device Test: 87.1 UVLO BP5H Rise Thresh VIN_14V





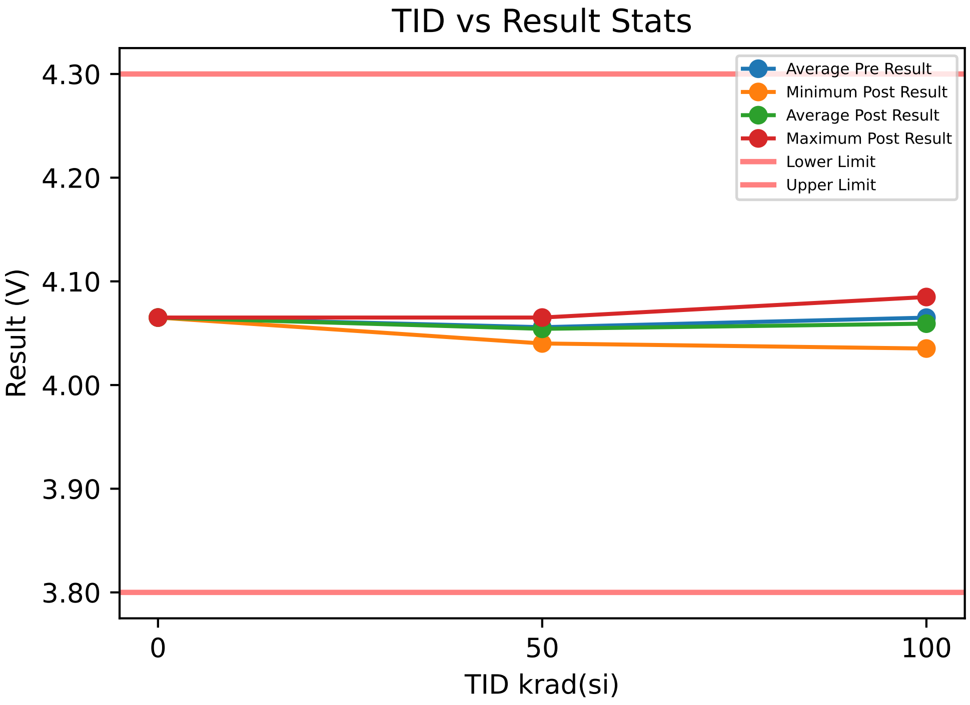
Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

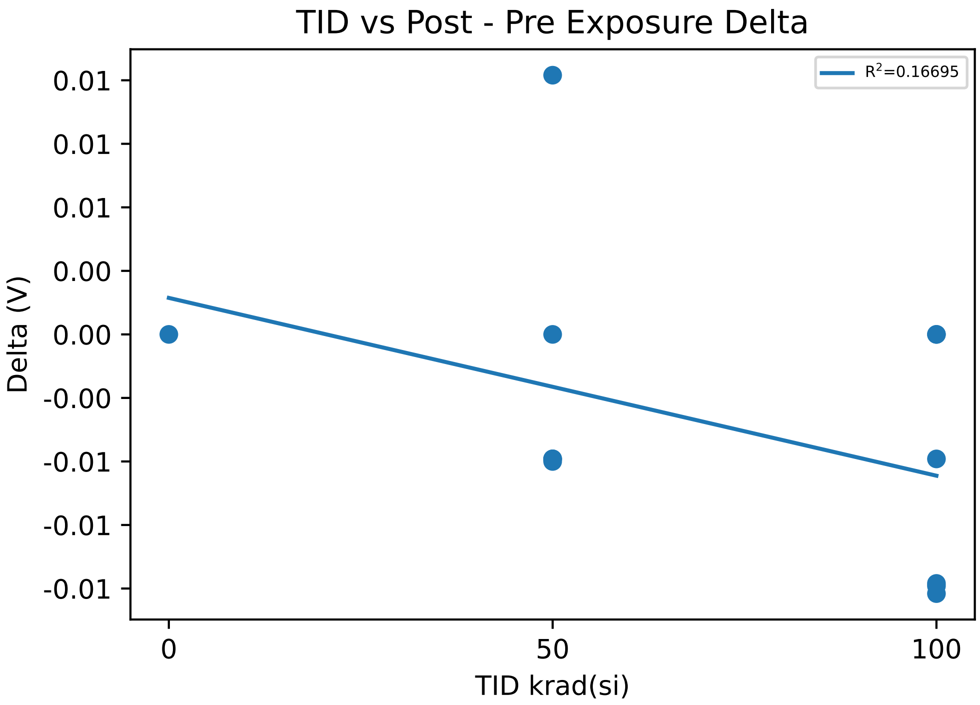
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.255	4.2451	-0.0099
60	50	Biased	4.2401	4.2299	-0.0102
61	50	Biased	4.25	4.2451	-0.0049
63	100	Biased	4.28	4.28	0
64	100	Biased	4.2401	4.2299	-0.0102
65	100	Biased	4.25	4.2451	-0.0049
66	50	Unbiased	4.2599	4.2599	0
67	50	Unbiased	4.2599	4.25	-0.0099
68	50	Unbiased	4.25	4.2599	0.0099
69	100	Unbiased	4.2599	4.25	-0.0099
70	100	Unbiased	4.2648	4.2599	-0.0049
71	100	Unbiased	4.2599	4.2599	0
72	0	Control	4.2599	4.2599	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.2599	4.2599	4.2599		4.2599	4.2599	4.2599		0	0	0	
50	4.2401	4.2525	4.2599	0.0075104	4.2299	4.2483	4.2599	0.011234	-0.0102	-0.0041667	0.0099	0.0079739
100	4.2401	4.2591	4.28	0.013523	4.2299	4.2541	4.28	0.016861	-0.0102	-0.0049833	0	0.004496

Device Test: 87.2 UVLO BP5H Fall Thresh VIN_14V





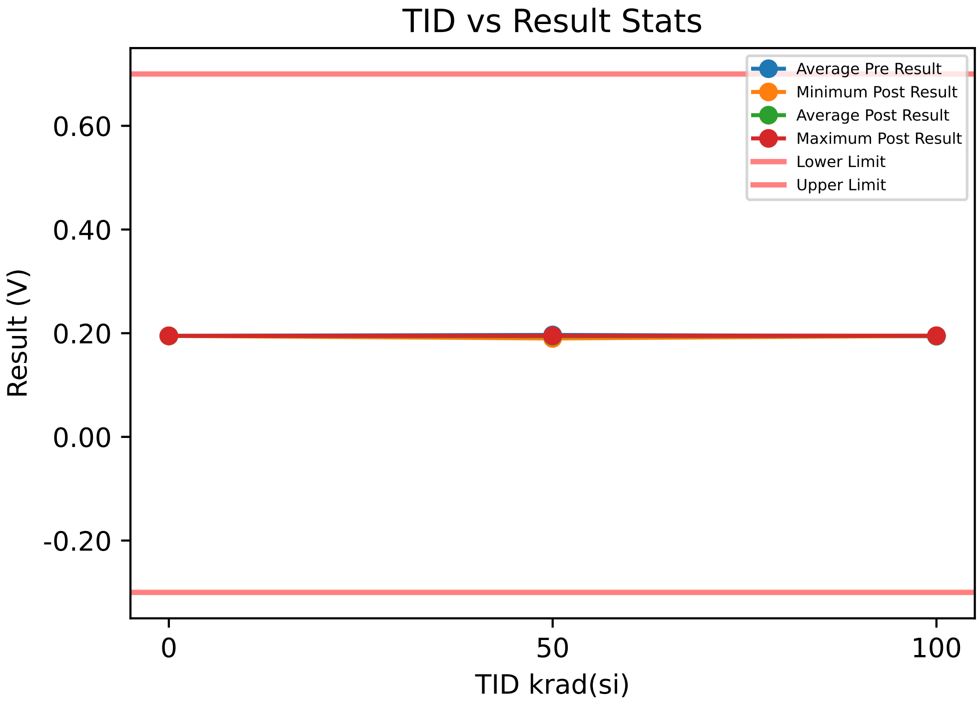
Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

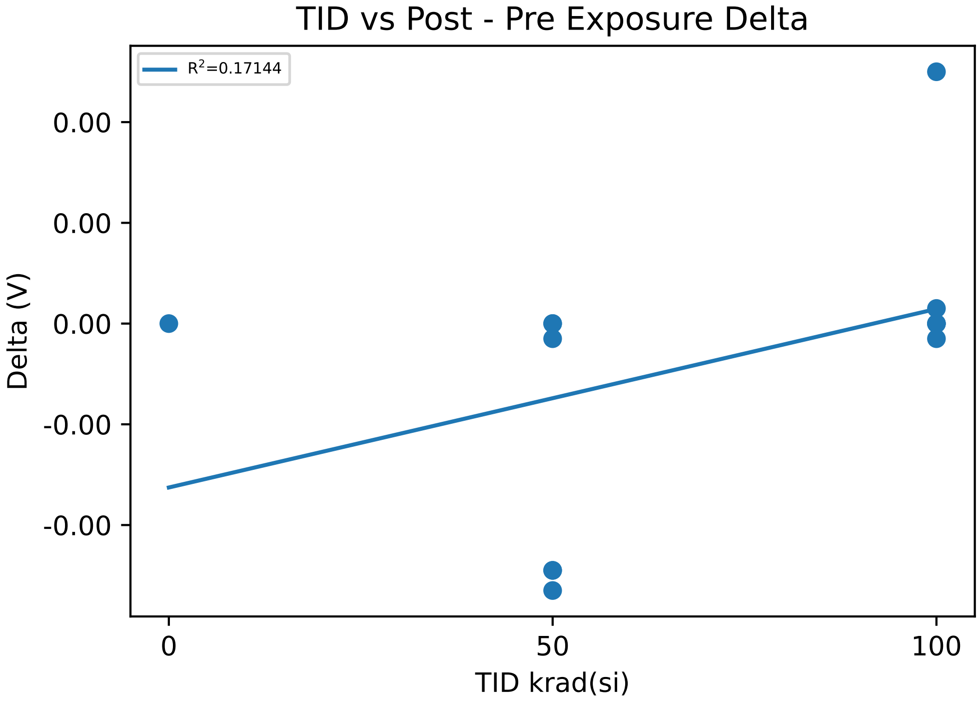
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.0549	4.05	-0.0049
60	50	Biased	4.045	4.0401	-0.0049
61	50	Biased	4.0549	4.05	-0.0049
63	100	Biased	4.0849	4.0849	0
64	100	Biased	4.045	4.0352	-0.0098
65	100	Biased	4.0549	4.05	-0.0049
66	50	Unbiased	4.0651	4.0651	0
67	50	Unbiased	4.0599	4.0549	-0.005
68	50	Unbiased	4.0549	4.0651	0.0102
69	100	Unbiased	4.0651	4.0549	-0.0102
70	100	Unbiased	4.075	4.0651	-0.0099
71	100	Unbiased	4.0651	4.0651	0
72	0	Control	4.0651	4.0651	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0651	4.0651	4.0651		4.0651	4.0651	4.0651		0	0	0	
50	4.045	4.0558	4.0651	0.0066689	4.0401	4.0542	4.0651	0.009718	-0.005	-0.0015833	0.0102	0.0060996
100	4.045	4.065	4.0849	0.014128	4.0352	4.0592	4.0849	0.016788	-0.0102	-0.0058	0	0.0049043

Device Test: 87.3 UVLO BP5H Thresh Hysteresis VIN_14V





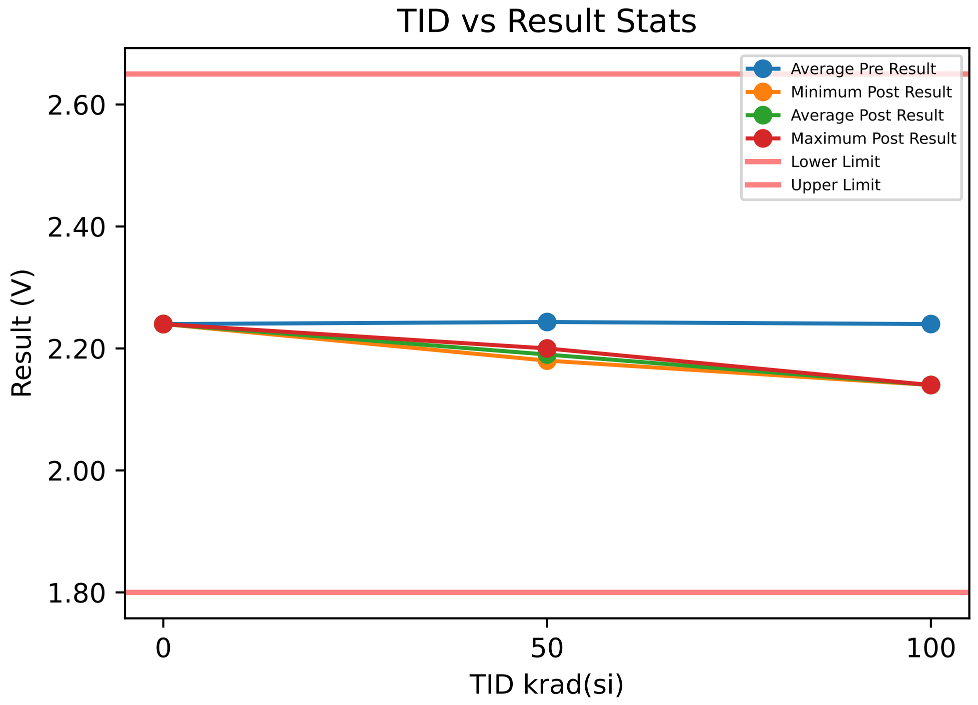
Test Results (Lower Limit = -0.3, Upper Limit = 0.7 (V))

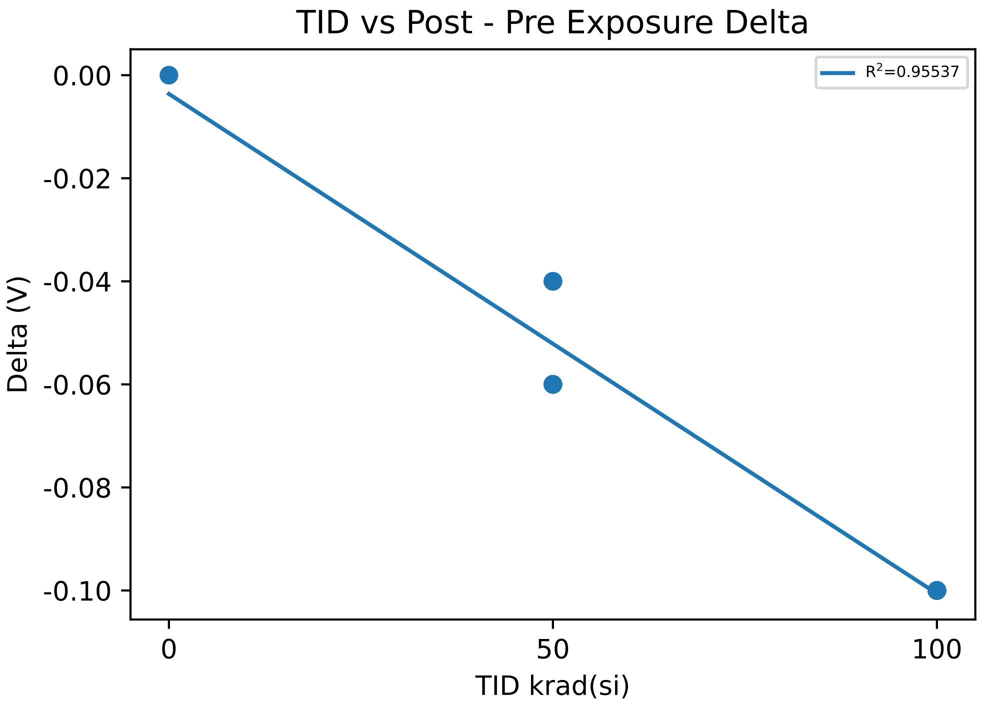
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.2	0.1951	-0.0049
60	50	Biased	0.1951	0.1898	-0.0053
61	50	Biased	0.1951	0.1951	0
63	100	Biased	0.1951	0.1951	0
64	100	Biased	0.1951	0.1948	-0.0003
65	100	Biased	0.1951	0.1951	0
66	50	Unbiased	0.1948	0.1948	0
67	50	Unbiased	0.2	0.1951	-0.0049
68	50	Unbiased	0.1951	0.1948	-0.0003
69	100	Unbiased	0.1948	0.1951	0.0003
70	100	Unbiased	0.1898	0.1948	0.005
71	100	Unbiased	0.1948	0.1948	0
72	0	Control	0.1948	0.1948	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1948	0.1948	0.1948		0.1948	0.1948	0.1948		0	0	0	
50	0.1948	0.19668	0.2	0.0025717	0.1898	0.19412	0.1951	0.0021198	-0.0053	-0.0025667	0	0.0027083
100	0.1898	0.19412	0.1951	0.0021198	0.1948	0.19495	0.1951	0.00016432	-0.0003	0.00083333	0.005	0.00205

Device Test: 90.0 PWM_LI Rise Thresh VIN_10V





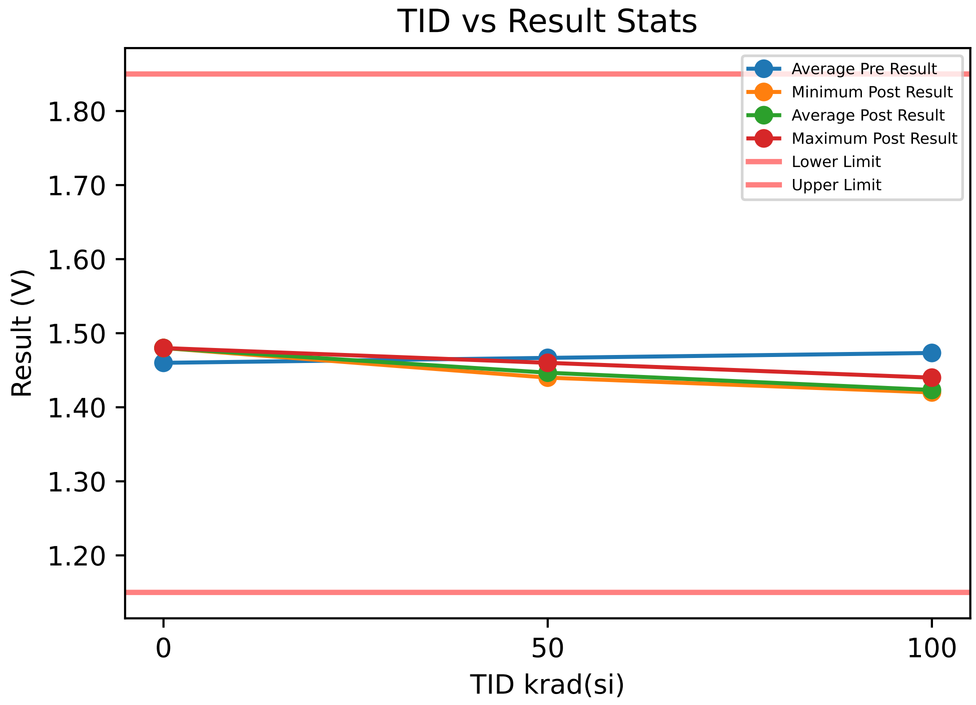
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

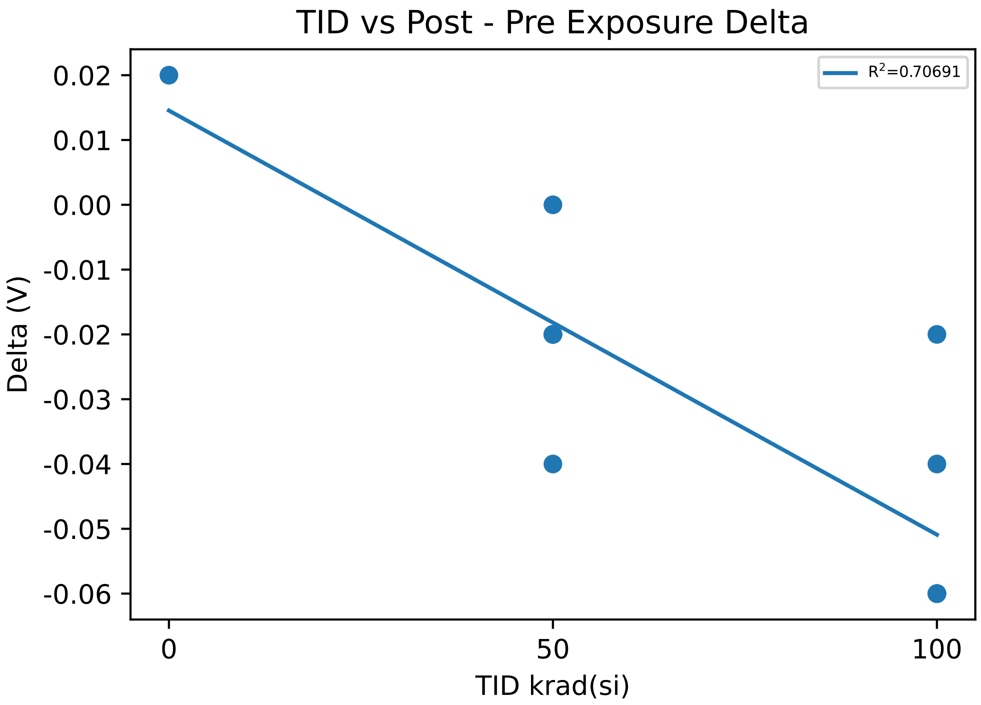
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.24	2.2	-0.04
60	50	Biased	2.24	2.18	-0.06
61	50	Biased	2.24	2.2	-0.04
63	100	Biased	2.24	2.14	-0.1
64	100	Biased	2.24	2.14	-0.1
65	100	Biased	2.24	2.14	-0.1
66	50	Unbiased	2.24	2.18	-0.06
67	50	Unbiased	2.24	2.18	-0.06
68	50	Unbiased	2.26	2.2	-0.06
69	100	Unbiased	2.24	2.14	-0.1
70	100	Unbiased	2.24	2.14	-0.1
71	100	Unbiased	2.24	2.14	-0.1
72	0	Control	2.24	2.24	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.24	2.24	2.24		2.24	2.24	2.24		0	0	0	
50	2.24	2.2433	2.26	0.008165	2.18	2.19	2.2	0.010954	-0.06	-0.053333	-0.04	0.010328
100	2.24	2.24	2.24	0	2.14	2.14	2.14	0	-0.1	-0.1	-0.1	0

Device Test: 90.1 PWM_LI Fall Thresh VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

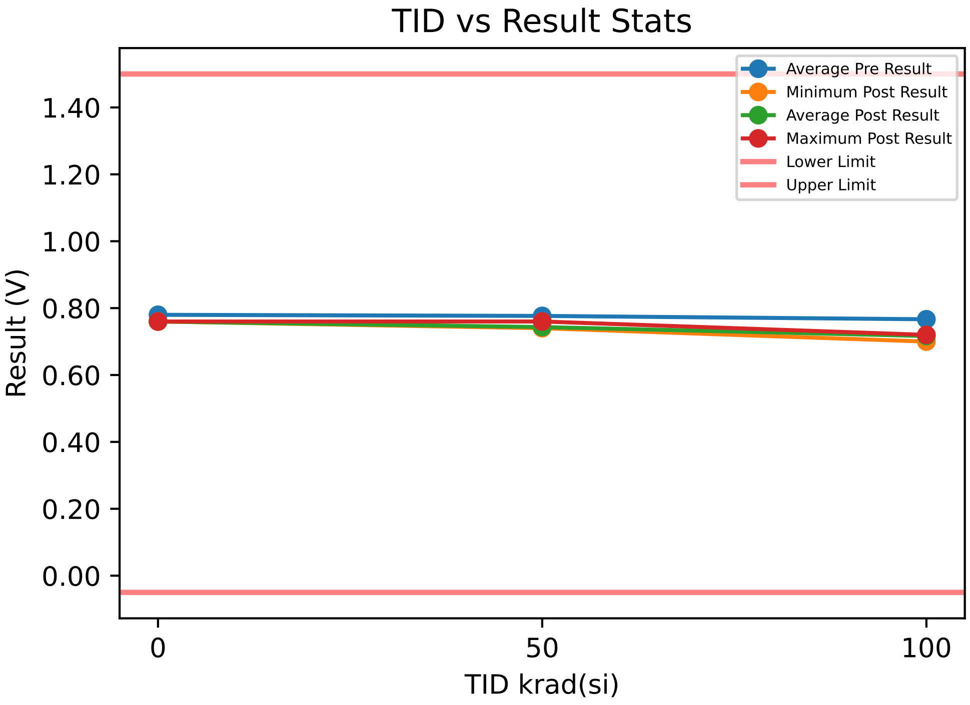
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

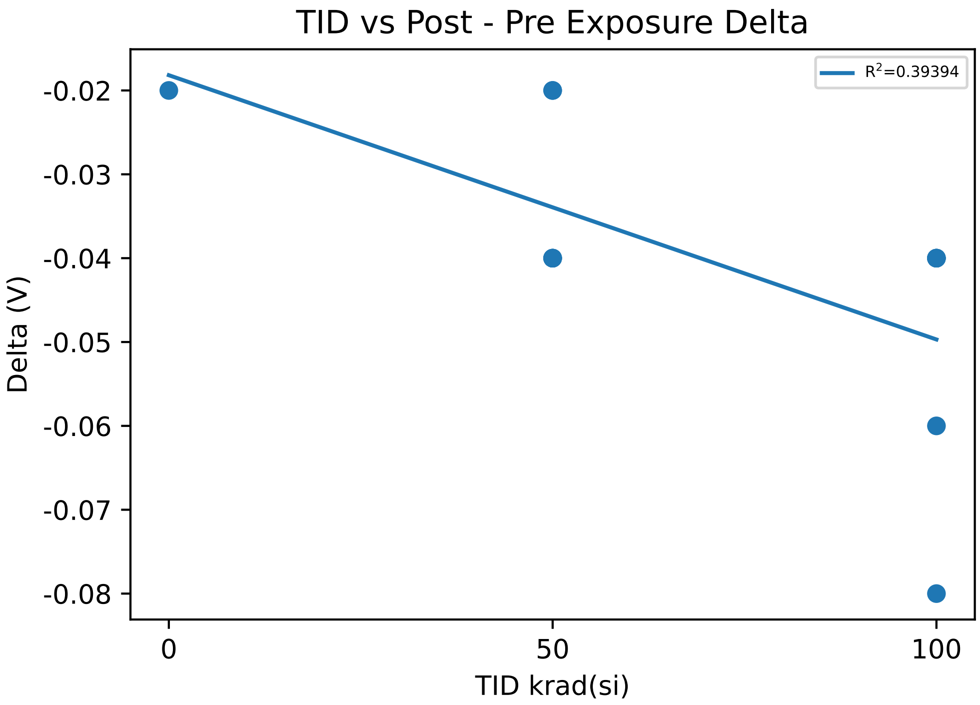
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.46	1.44	-0.02
60	50	Biased	1.46	1.44	-0.02
61	50	Biased	1.46	1.46	0
63	100	Biased	1.48	1.42	-0.06
64	100	Biased	1.46	1.42	-0.04
65	100	Biased	1.46	1.44	-0.02
66	50	Unbiased	1.46	1.44	-0.02
67	50	Unbiased	1.48	1.44	-0.04
68	50	Unbiased	1.48	1.46	-0.02
69	100	Unbiased	1.48	1.42	-0.06
70	100	Unbiased	1.48	1.42	-0.06
71	100	Unbiased	1.48	1.42	-0.06
72	0	Control	1.46	1.48	0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.46	1.46	1.46		1.48	1.48	1.48		0.02	0.02	0.02	
50	1.46	1.4667	1.48	0.010328	1.44	1.4467	1.46	0.010328	-0.04	-0.02	0	0.012649
100	1.46	1.4733	1.48	0.010328	1.42	1.4233	1.44	0.008165	-0.06	-0.05	-0.02	0.016733

Device Test: 90.2 PWM_LI Thresh Hysteresis VIN_10V





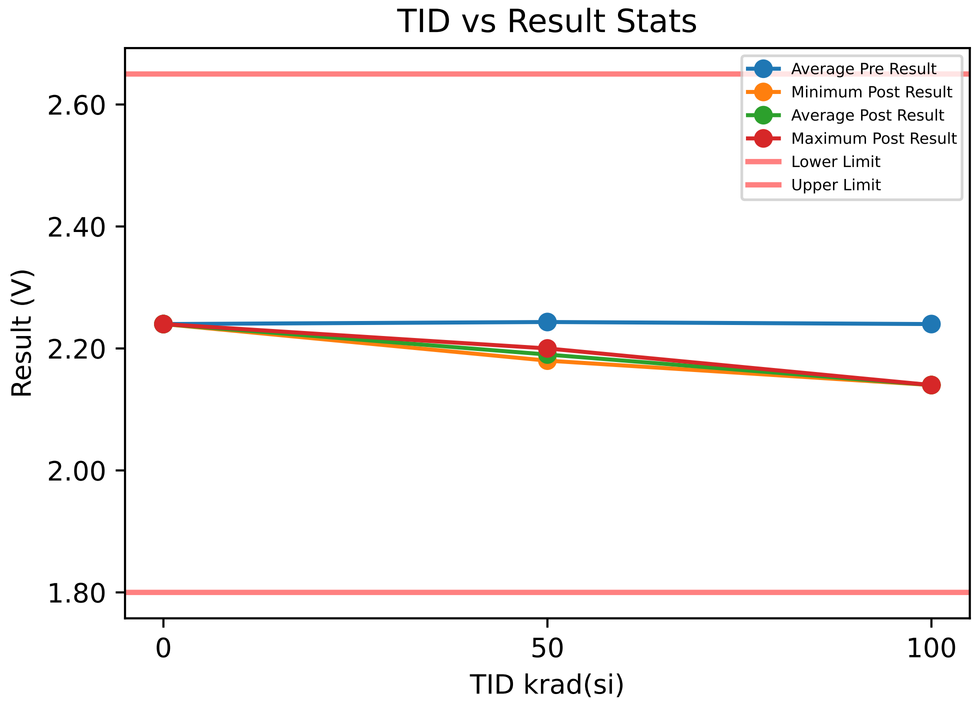
Test Results (Lower Limit = -0.05, Upper Limit = 1.5 (V))

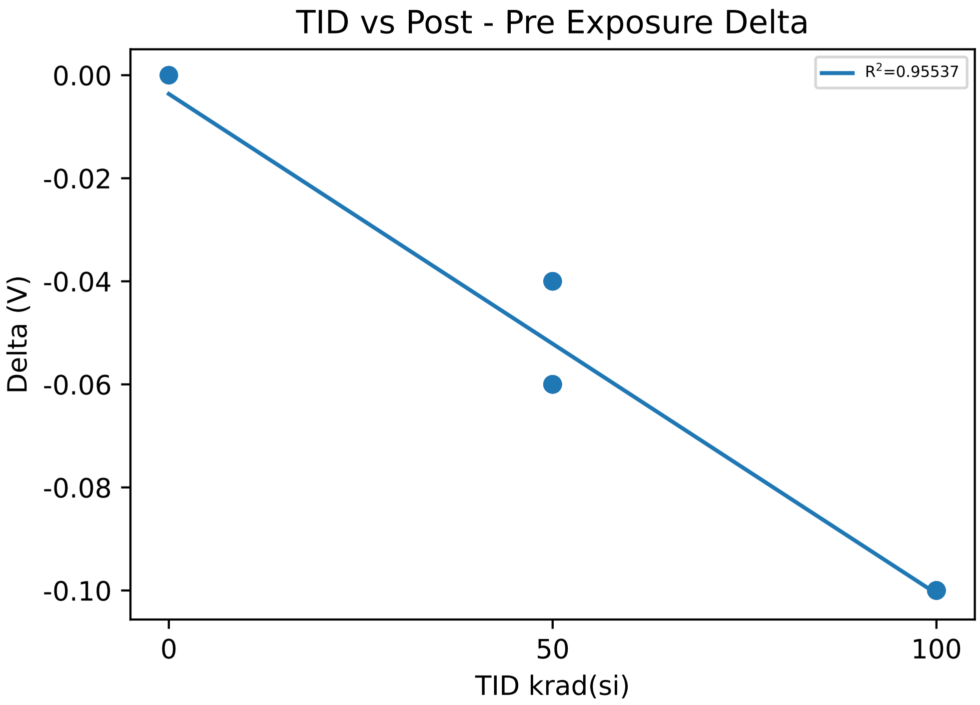
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.78	0.76	-0.02
60	50	Biased	0.78	0.74	-0.04
61	50	Biased	0.78	0.74	-0.04
63	100	Biased	0.76	0.72	-0.04
64	100	Biased	0.78	0.72	-0.06
65	100	Biased	0.78	0.7	-0.08
66	50	Unbiased	0.78	0.74	-0.04
67	50	Unbiased	0.76	0.74	-0.02
68	50	Unbiased	0.78	0.74	-0.04
69	100	Unbiased	0.76	0.72	-0.04
70	100	Unbiased	0.76	0.72	-0.04
71	100	Unbiased	0.76	0.72	-0.04
72	0	Control	0.78	0.76	-0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.78	0.78	0.78		0.76	0.76	0.76		-0.02	-0.02	-0.02	
50	0.76	0.77667	0.78	0.008165	0.74	0.74333	0.76	0.008165	-0.04	-0.033333	-0.02	0.010328
100	0.76	0.76667	0.78	0.010328	0.7	0.71667	0.72	0.008165	-0.08	-0.05	-0.04	0.016733

Device Test: 90.3 EN_HI Rise Thresh VIN_10V





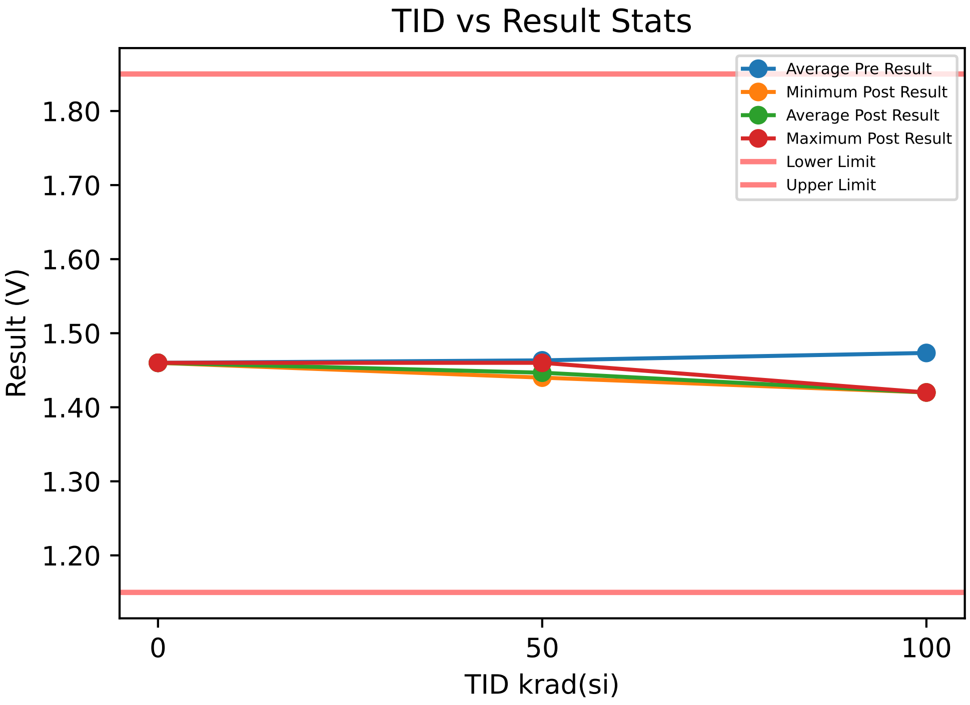
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

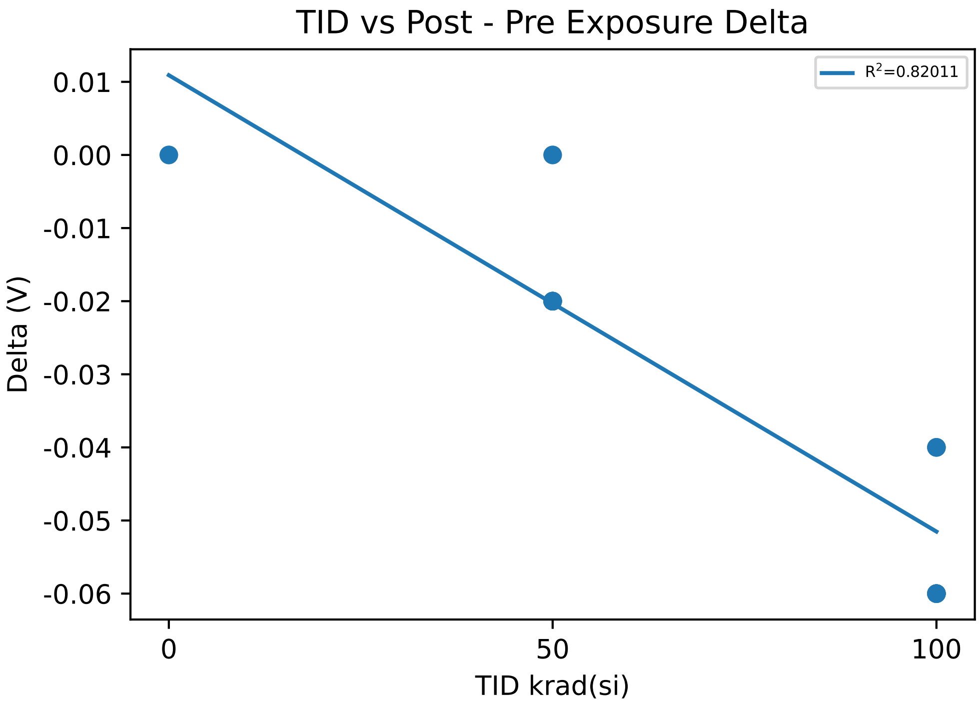
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.24	2.2	-0.04
60	50	Biased	2.24	2.18	-0.06
61	50	Biased	2.24	2.2	-0.04
63	100	Biased	2.24	2.14	-0.1
64	100	Biased	2.24	2.14	-0.1
65	100	Biased	2.24	2.14	-0.1
66	50	Unbiased	2.24	2.18	-0.06
67	50	Unbiased	2.24	2.18	-0.06
68	50	Unbiased	2.26	2.2	-0.06
69	100	Unbiased	2.24	2.14	-0.1
70	100	Unbiased	2.24	2.14	-0.1
71	100	Unbiased	2.24	2.14	-0.1
72	0	Control	2.24	2.24	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.24	2.24	2.24		2.24	2.24	2.24		0	0	0	
50	2.24	2.2433	2.26	0.008165	2.18	2.19	2.2	0.010954	-0.06	-0.053333	-0.04	0.010328
100	2.24	2.24	2.24	0	2.14	2.14	2.14	0	-0.1	-0.1	-0.1	0

Device Test: 90.4 EN_HI Fall Thresh VIN_10V





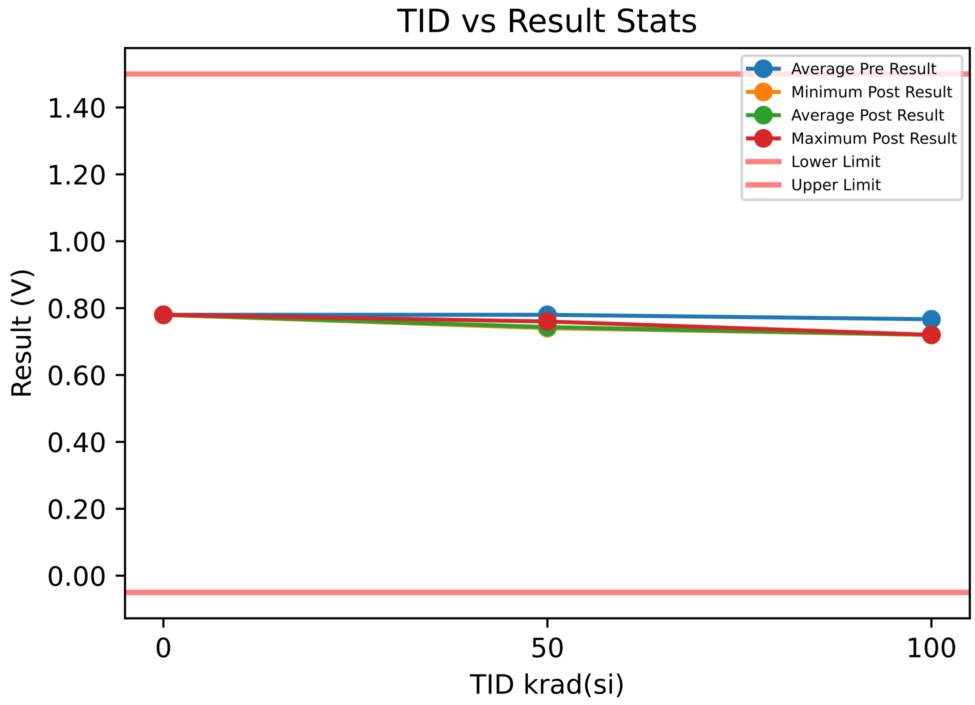
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

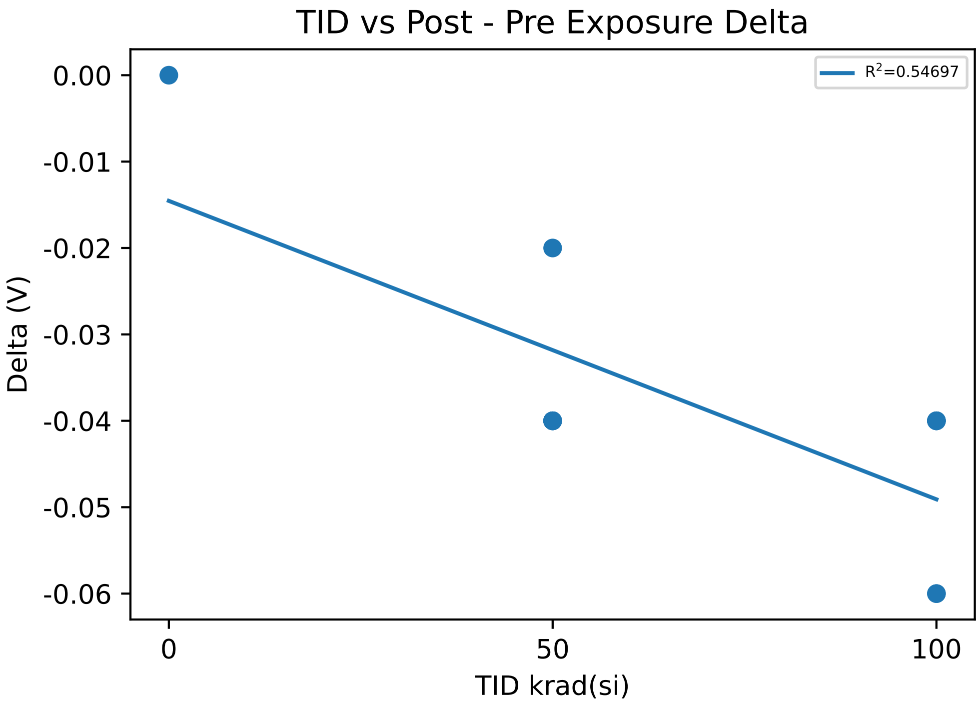
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.46	1.44	-0.02
60	50	Biased	1.46	1.44	-0.02
61	50	Biased	1.46	1.46	0
63	100	Biased	1.48	1.42	-0.06
64	100	Biased	1.46	1.42	-0.04
65	100	Biased	1.46	1.42	-0.04
66	50	Unbiased	1.46	1.44	-0.02
67	50	Unbiased	1.46	1.44	-0.02
68	50	Unbiased	1.48	1.46	-0.02
69	100	Unbiased	1.48	1.42	-0.06
70	100	Unbiased	1.48	1.42	-0.06
71	100	Unbiased	1.48	1.42	-0.06
72	0	Control	1.46	1.46	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.46	1.46	1.46		1.46	1.46	1.46		0	0	0	
50	1.46	1.4633	1.48	0.008165	1.44	1.4467	1.46	0.010328	-0.02	-0.016667	0	0.008165
100	1.46	1.4733	1.48	0.010328	1.42	1.42	1.42	0	-0.06	-0.053333	-0.04	0.010328

Device Test: 90.5 EN_HI Thresh Hysteresis VIN_10V





Test Results (Lower Limit = -0.05, Upper Limit = 1.5 (V))

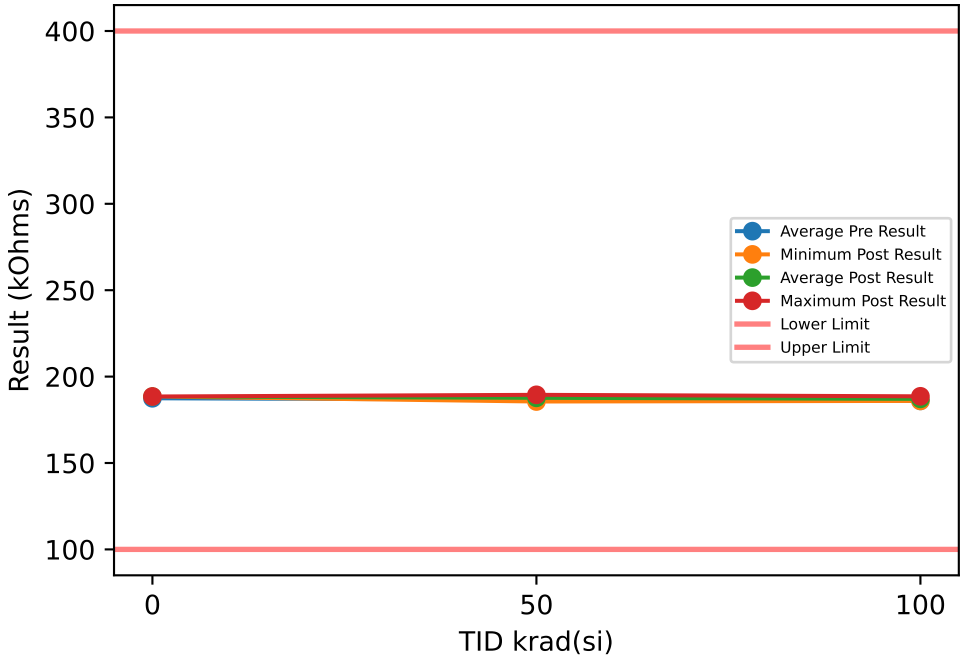
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.78	0.76	-0.02
60	50	Biased	0.78	0.74	-0.04
61	50	Biased	0.78	0.74	-0.04
63	100	Biased	0.76	0.72	-0.04
64	100	Biased	0.78	0.72	-0.06
65	100	Biased	0.78	0.72	-0.06
66	50	Unbiased	0.78	0.74	-0.04
67	50	Unbiased	0.78	0.74	-0.04
68	50	Unbiased	0.78	0.74	-0.04
69	100	Unbiased	0.76	0.72	-0.04
70	100	Unbiased	0.76	0.72	-0.04
71	100	Unbiased	0.76	0.72	-0.04
72	0	Control	0.78	0.78	0

Test Statistics (V)

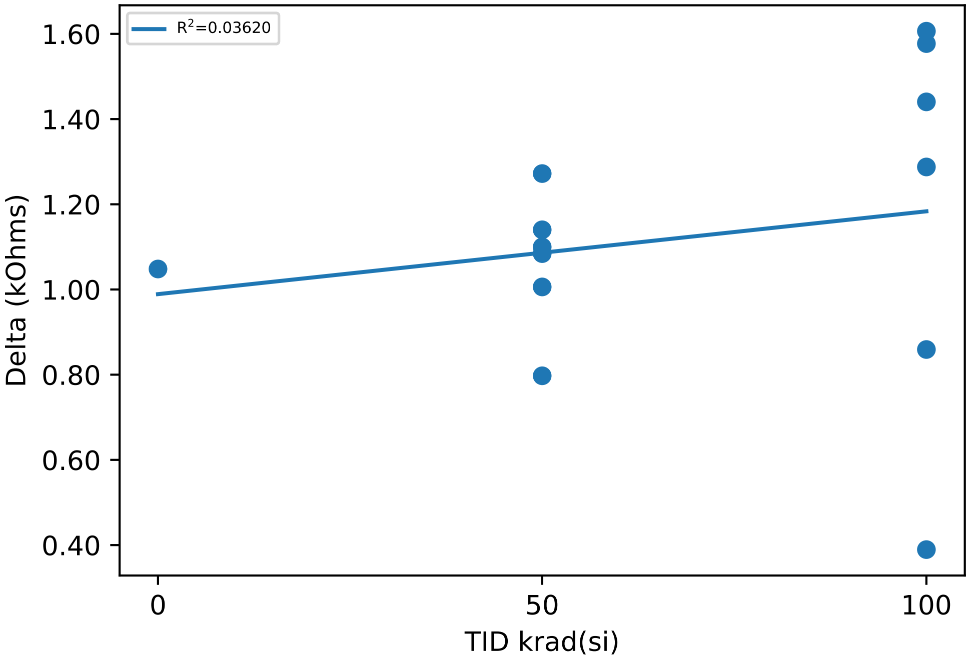
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.78	0.78	0.78		0.78	0.78	0.78		0	0	0	
50	0.78	0.78	0.78	0	0.74	0.74333	0.76	0.008165	-0.04	-0.036667	-0.02	0.008165
100	0.76	0.76667	0.78	0.010328	0.72	0.72	0.72	0	-0.06	-0.046667	-0.04	0.010328

Device Test: 90.6 PWM_LI Pull Down Resistance VIN_10V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



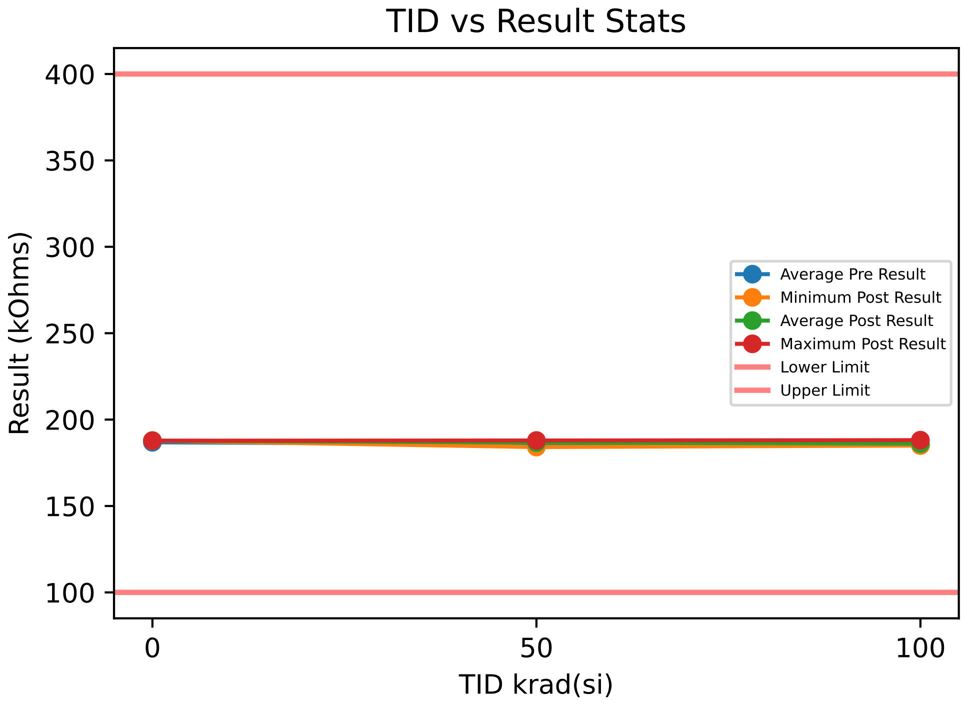
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kOhms))

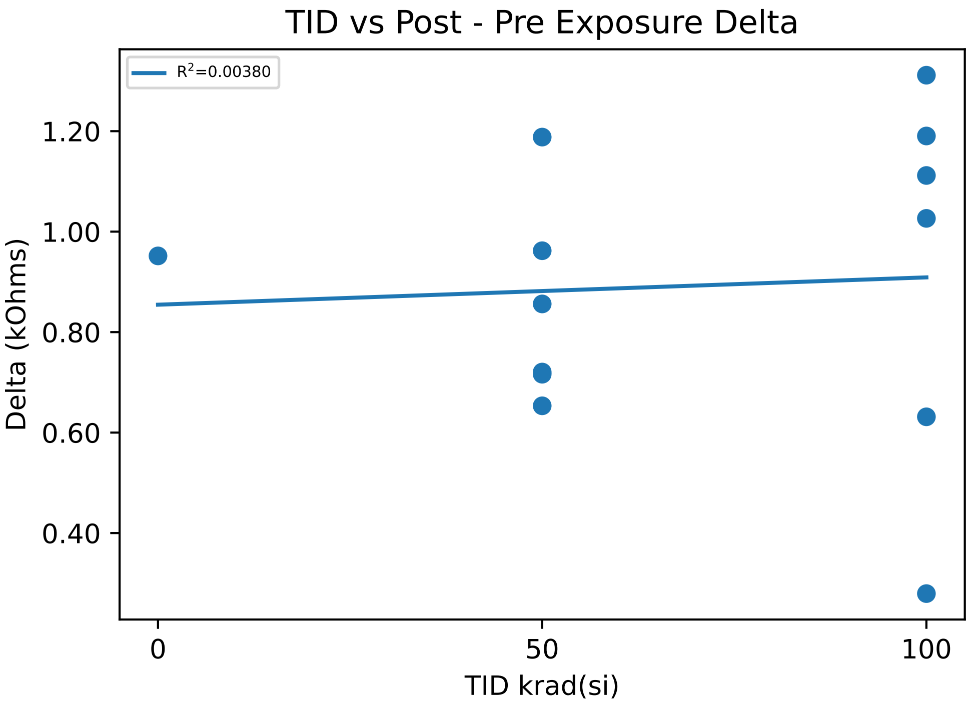
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	187.47	188.61	1.1401
60	50	Biased	188.45	189.45	1.006
61	50	Biased	188.03	189.13	1.0998
63	100	Biased	186.85	188.29	1.4404
64	100	Biased	186.99	188.6	1.6063
65	100	Biased	185.64	187.21	1.5772
66	50	Unbiased	184.78	185.57	0.7974
67	50	Unbiased	186.51	187.59	1.0842
68	50	Unbiased	184.62	185.9	1.2721
69	100	Unbiased	185.69	186.55	0.8591
70	100	Unbiased	185.53	185.92	0.3894
71	100	Unbiased	184.79	186.08	1.2876
72	0	Control	187.45	188.49	1.0481

Test Statistics (kOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	187.45	187.45	187.45		188.49	188.49	188.49		1.0481	1.0481	1.0481	
50	184.62	186.64	188.45	1.6387	185.57	187.71	189.45	1.6564	0.7974	1.0666	1.2721	0.15823
100	184.79	185.92	186.99	0.84578	185.92	187.11	188.6	1.1325	0.3894	1.1933	1.6063	0.47872

Device Test: 90.7 EN_HI Pull Down Resistance VIN_10V





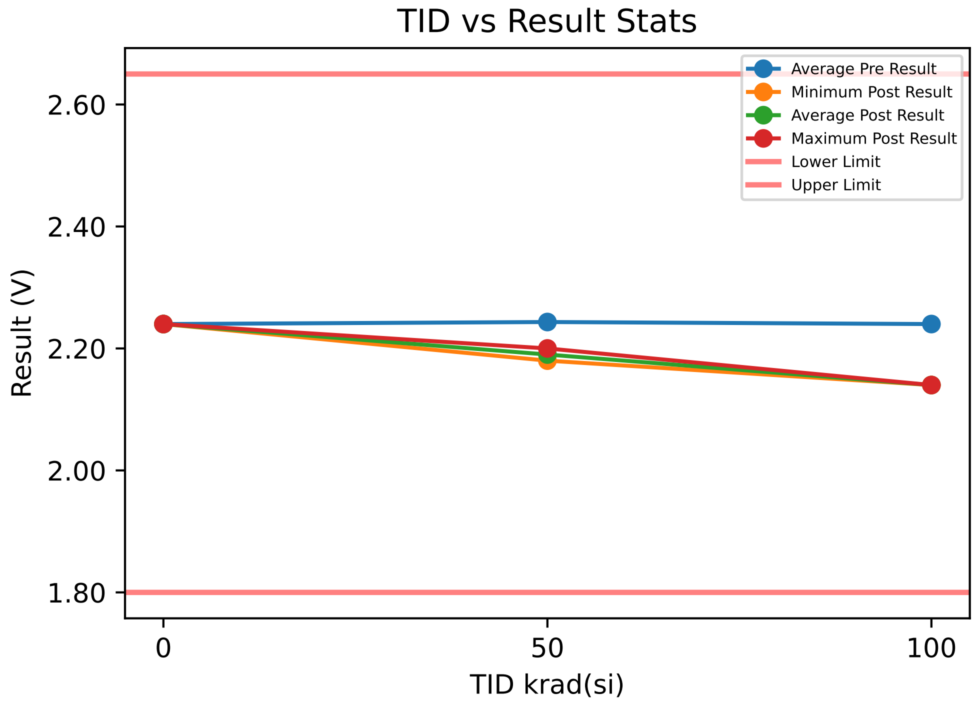
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kOhms))

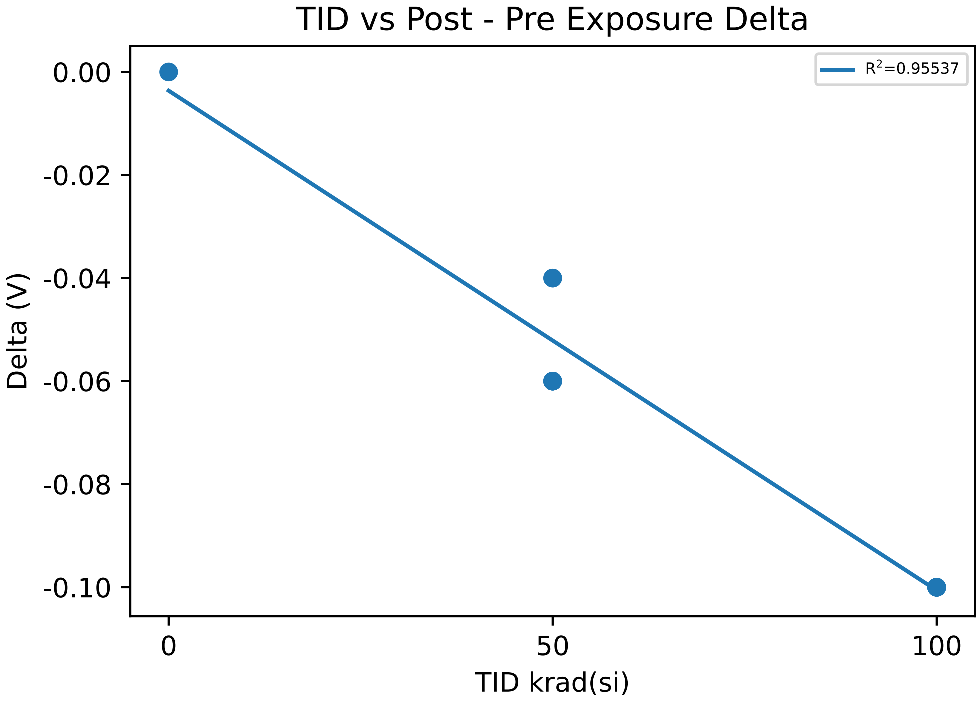
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	186.86	187.57	0.7162
60	50	Biased	186.8	187.76	0.962
61	50	Biased	187.25	187.91	0.6533
63	100	Biased	185.62	186.65	1.0264
64	100	Biased	186.91	188.1	1.1904
65	100	Biased	185.1	186.41	1.3114
66	50	Unbiased	183.39	184.11	0.7205
67	50	Unbiased	186.35	187.2	0.8561
68	50	Unbiased	184.33	185.52	1.1882
69	100	Unbiased	184.36	184.99	0.6314
70	100	Unbiased	184.77	185.05	0.2795
71	100	Unbiased	184.29	185.4	1.1118
72	0	Control	186.85	187.8	0.9517

Test Statistics (kOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	186.85	186.85	186.85		187.8	187.8	187.8		0.9517	0.9517	0.9517	
50	183.39	185.83	187.25	1.5801	184.11	186.68	187.91	1.5289	0.6533	0.84938	1.1882	0.20016
100	184.29	185.18	186.91	0.98248	184.99	186.1	188.1	1.2014	0.2795	0.92515	1.3114	0.39186

Device Test: 91.0 PWM_LI Rise Thresh VIN_12V





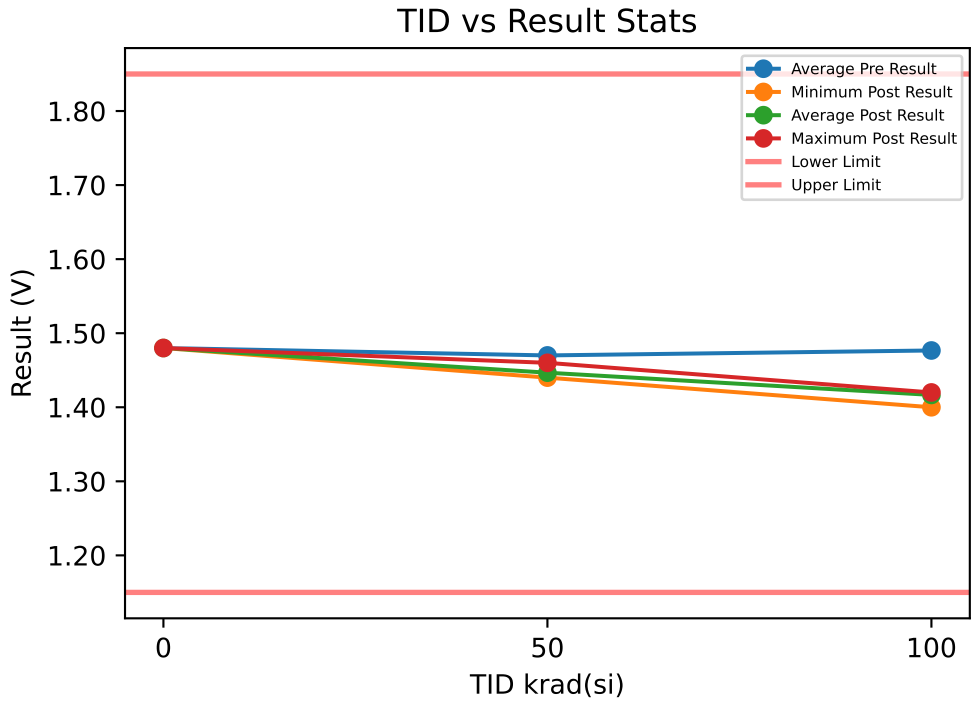
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

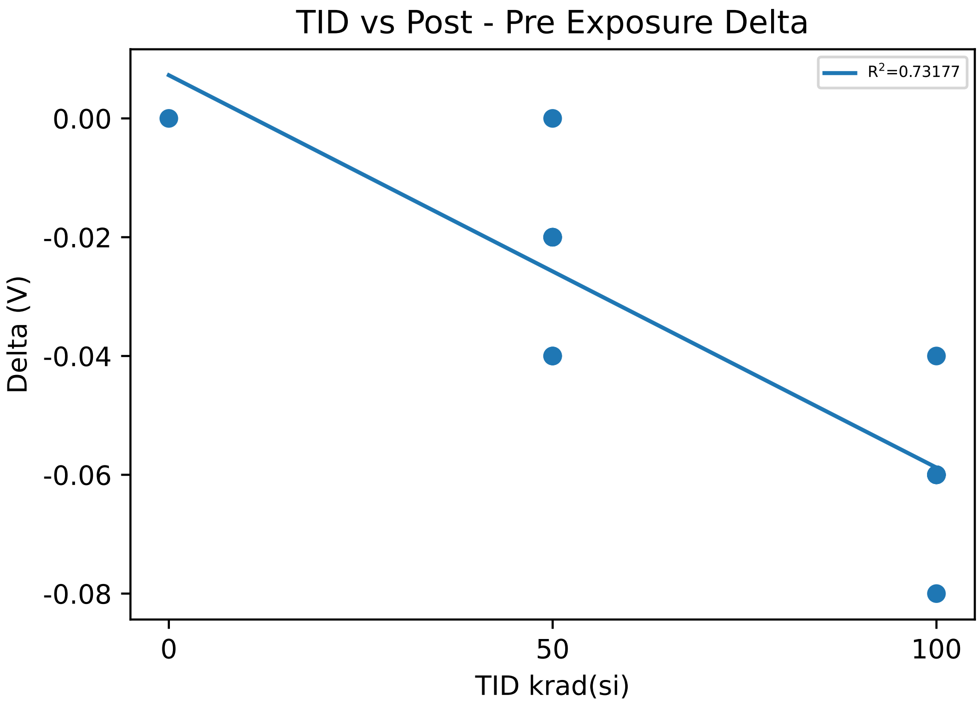
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.24	2.2	-0.04
60	50	Biased	2.24	2.18	-0.06
61	50	Biased	2.24	2.2	-0.04
63	100	Biased	2.24	2.14	-0.1
64	100	Biased	2.24	2.14	-0.1
65	100	Biased	2.24	2.14	-0.1
66	50	Unbiased	2.24	2.18	-0.06
67	50	Unbiased	2.24	2.18	-0.06
68	50	Unbiased	2.26	2.2	-0.06
69	100	Unbiased	2.24	2.14	-0.1
70	100	Unbiased	2.24	2.14	-0.1
71	100	Unbiased	2.24	2.14	-0.1
72	0	Control	2.24	2.24	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.24	2.24	2.24		2.24	2.24	2.24		0	0	0	
50	2.24	2.2433	2.26	0.008165	2.18	2.19	2.2	0.010954	-0.06	-0.053333	-0.04	0.010328
100	2.24	2.24	2.24	0	2.14	2.14	2.14	0	-0.1	-0.1	-0.1	0

Device Test: 91.1 PWM_LI Fall Thresh VIN_12V





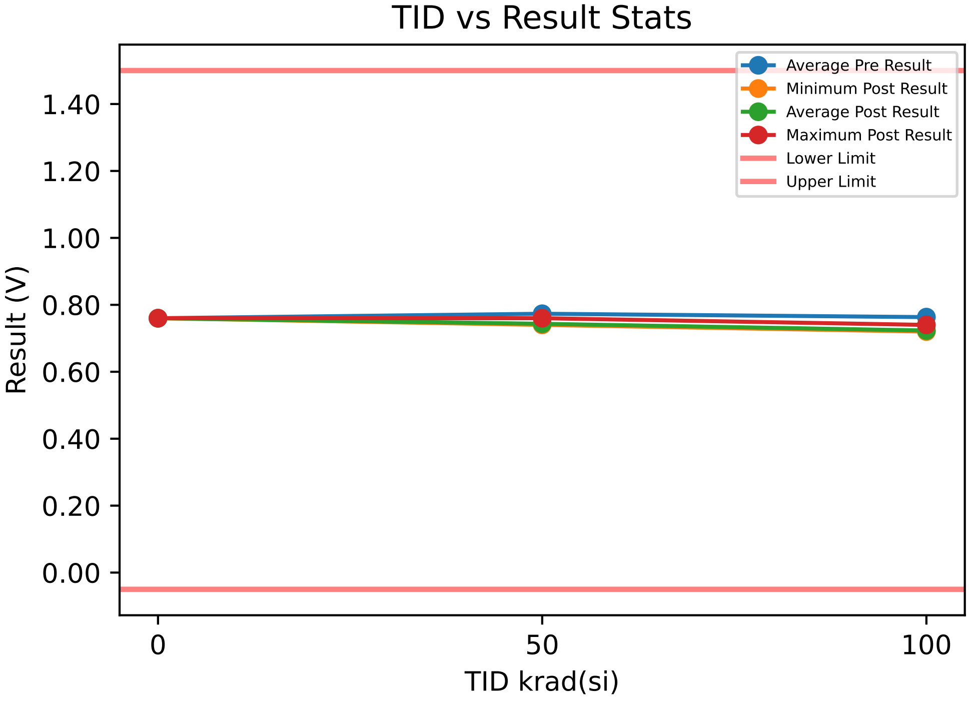
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

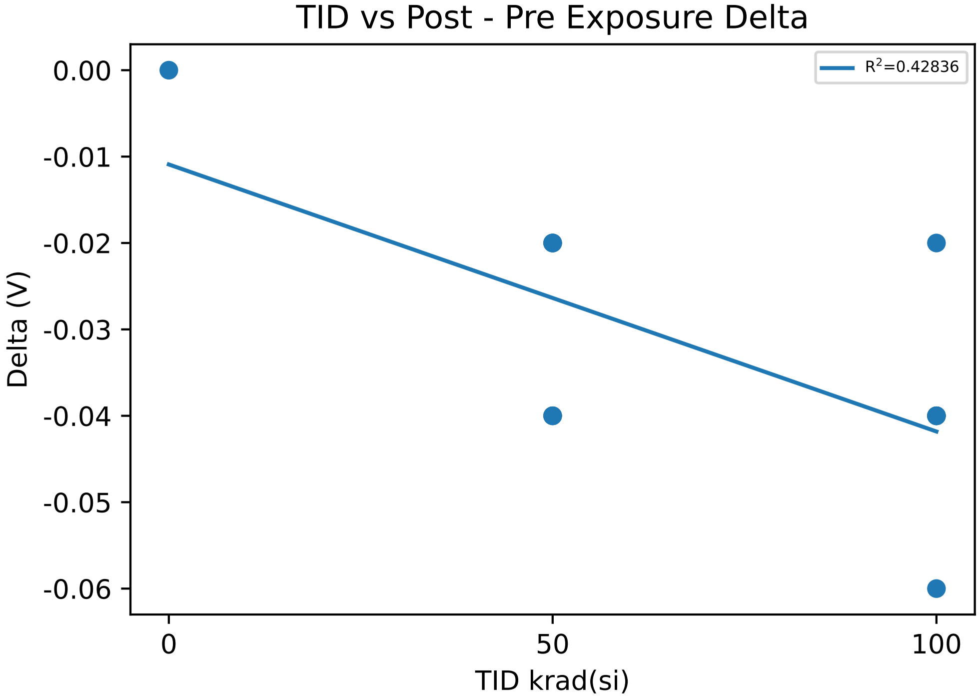
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.46	1.44	-0.02
60	50	Biased	1.46	1.44	-0.02
61	50	Biased	1.46	1.46	0
63	100	Biased	1.48	1.42	-0.06
64	100	Biased	1.46	1.42	-0.04
65	100	Biased	1.48	1.42	-0.06
66	50	Unbiased	1.48	1.44	-0.04
67	50	Unbiased	1.48	1.44	-0.04
68	50	Unbiased	1.48	1.46	-0.02
69	100	Unbiased	1.48	1.42	-0.06
70	100	Unbiased	1.48	1.42	-0.06
71	100	Unbiased	1.48	1.4	-0.08
72	0	Control	1.48	1.48	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48		1.48	1.48	1.48		0	0	0	
50	1.46	1.47	1.48	0.010954	1.44	1.4467	1.46	0.010328	-0.04	-0.023333	0	0.015055
100	1.46	1.4767	1.48	0.008165	1.4	1.4167	1.42	0.008165	-0.08	-0.06	-0.04	0.012649

Device Test: 91.2 PWM_LI Thresh Hysteresis VIN_12V





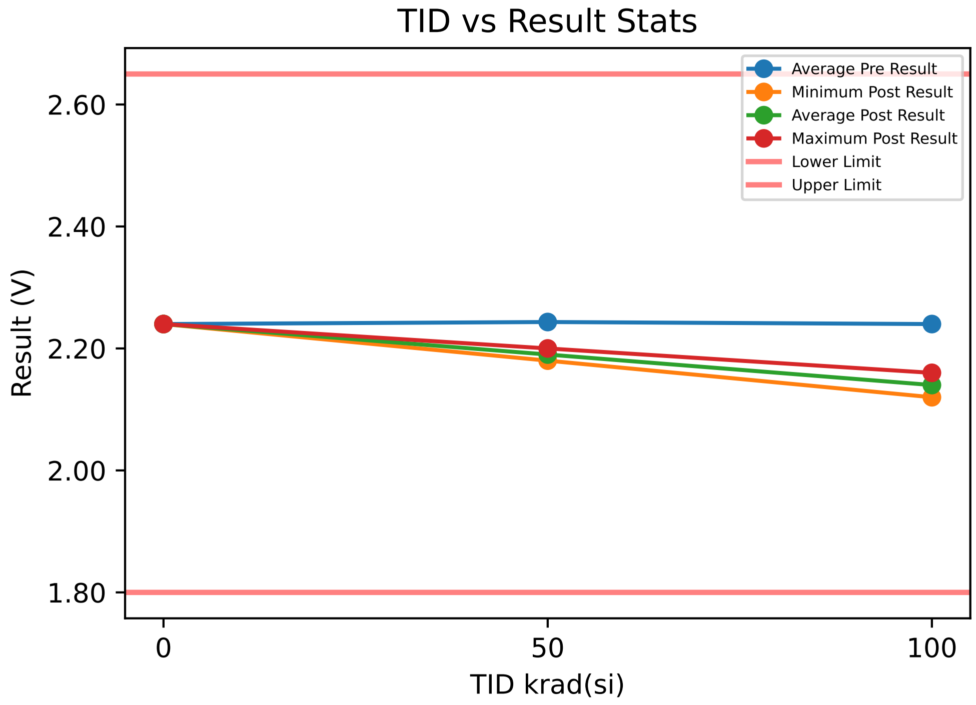
Test Results (Lower Limit = -0.05, Upper Limit = 1.5 (V))

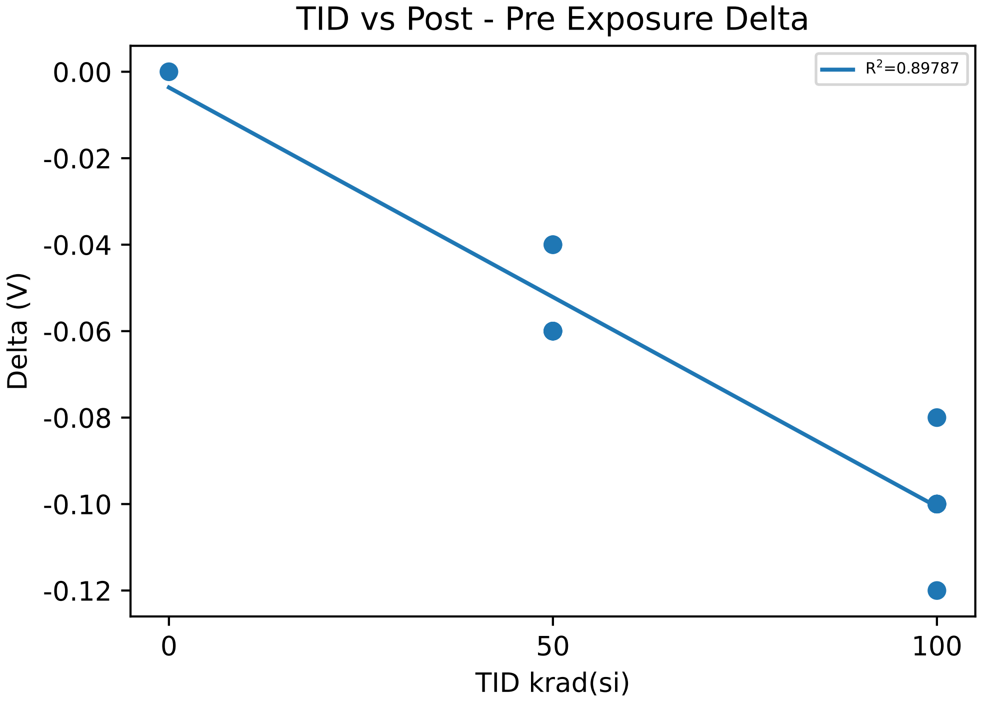
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.78	0.76	-0.02
60	50	Biased	0.78	0.74	-0.04
61	50	Biased	0.78	0.74	-0.04
63	100	Biased	0.76	0.72	-0.04
64	100	Biased	0.78	0.72	-0.06
65	100	Biased	0.76	0.72	-0.04
66	50	Unbiased	0.76	0.74	-0.02
67	50	Unbiased	0.76	0.74	-0.02
68	50	Unbiased	0.78	0.74	-0.04
69	100	Unbiased	0.76	0.72	-0.04
70	100	Unbiased	0.76	0.72	-0.04
71	100	Unbiased	0.76	0.74	-0.02
72	0	Control	0.76	0.76	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.76	0.76	0.76		0.76	0.76	0.76		0	0	0	
50	0.76	0.77333	0.78	0.010328	0.74	0.74333	0.76	0.008165	-0.04	-0.03	-0.02	0.010954
100	0.76	0.76333	0.78	0.008165	0.72	0.72333	0.74	0.008165	-0.06	-0.04	-0.02	0.012649

Device Test: 91.3 EN_HI Rise Thresh VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

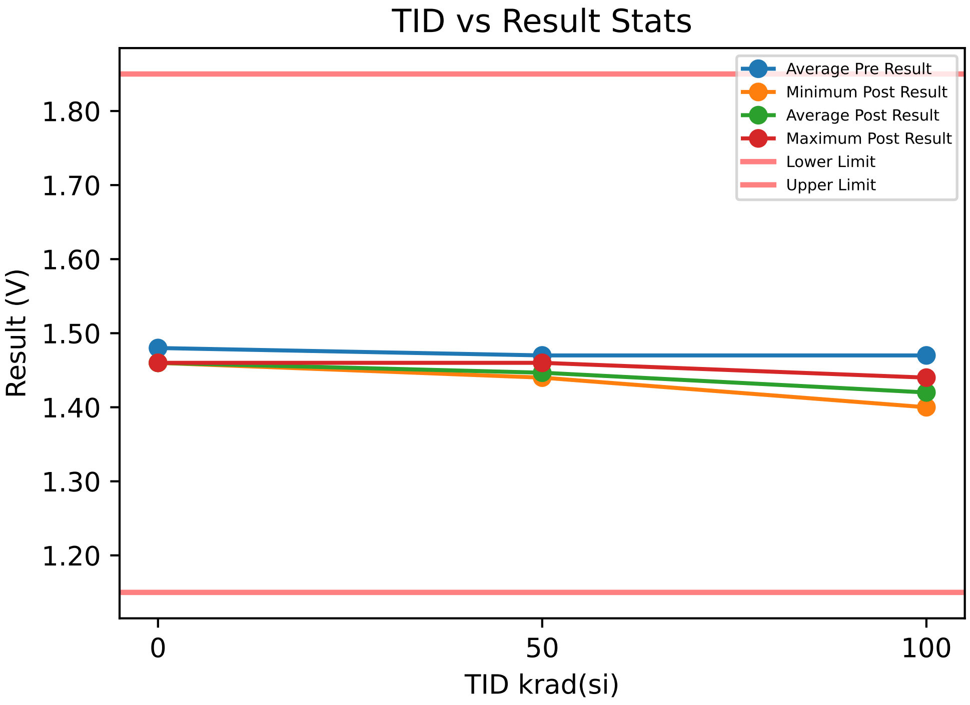
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

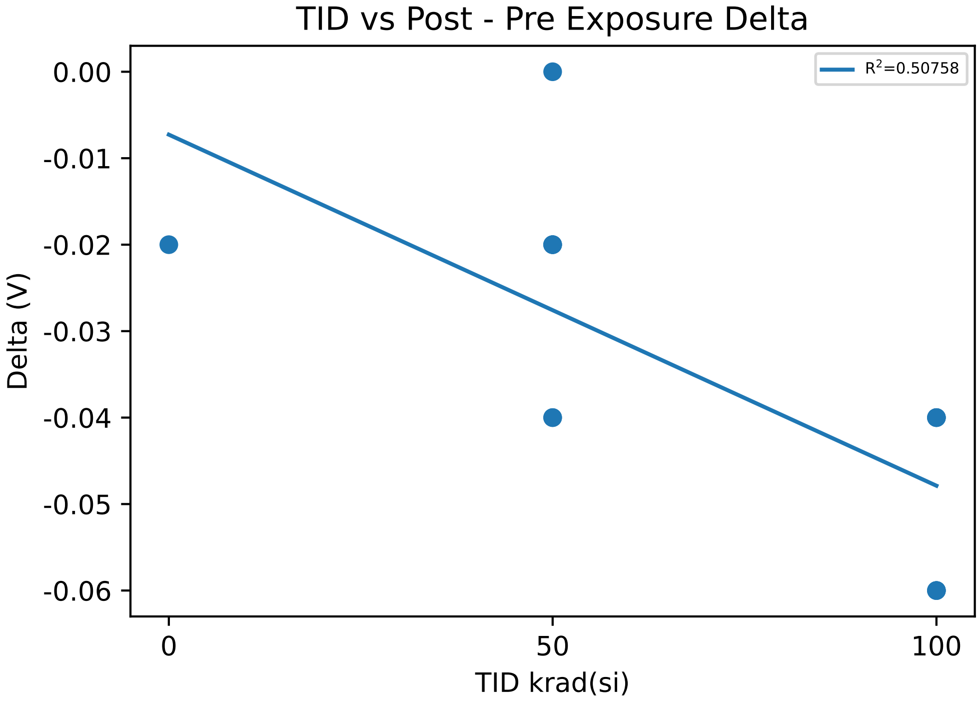
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.24	2.2	-0.04
60	50	Biased	2.24	2.18	-0.06
61	50	Biased	2.24	2.2	-0.04
63	100	Biased	2.24	2.14	-0.1
64	100	Biased	2.24	2.14	-0.1
65	100	Biased	2.24	2.14	-0.1
66	50	Unbiased	2.24	2.18	-0.06
67	50	Unbiased	2.24	2.18	-0.06
68	50	Unbiased	2.26	2.2	-0.06
69	100	Unbiased	2.24	2.16	-0.08
70	100	Unbiased	2.24	2.14	-0.1
71	100	Unbiased	2.24	2.12	-0.12
72	0	Control	2.24	2.24	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.24	2.24	2.24		2.24	2.24	2.24		0	0	0	
50	2.24	2.2433	2.26	0.008165	2.18	2.19	2.2	0.010954	-0.06	-0.053333	-0.04	0.010328
100	2.24	2.24	2.24	0	2.12	2.14	2.16	0.012649	-0.12	-0.1	-0.08	0.012649

Device Test: 91.4 EN_HI Fall Thresh VIN_12V





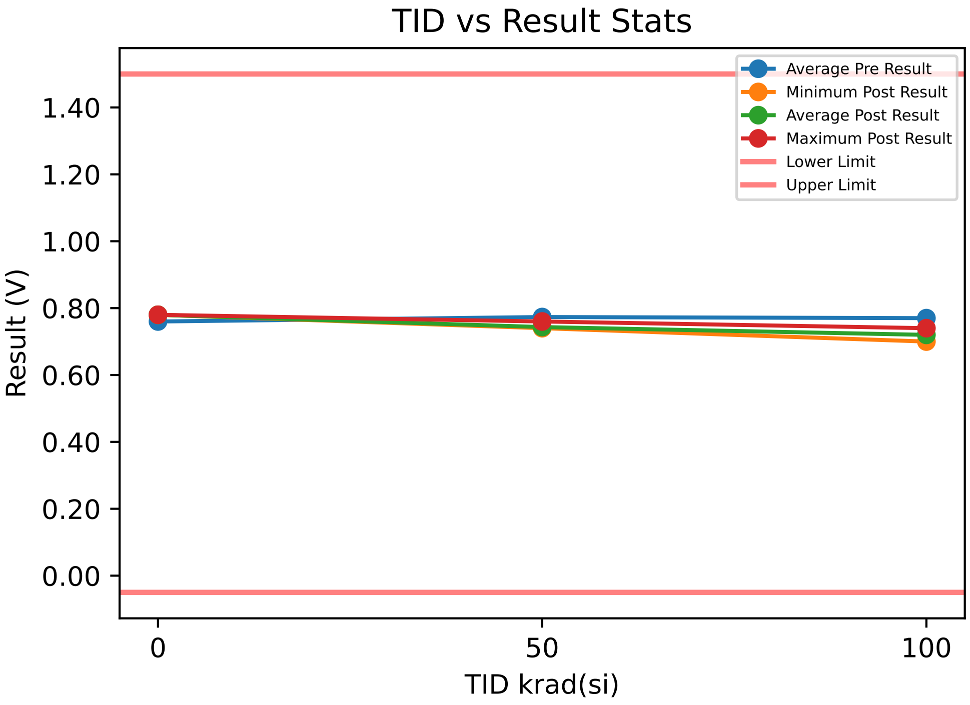
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

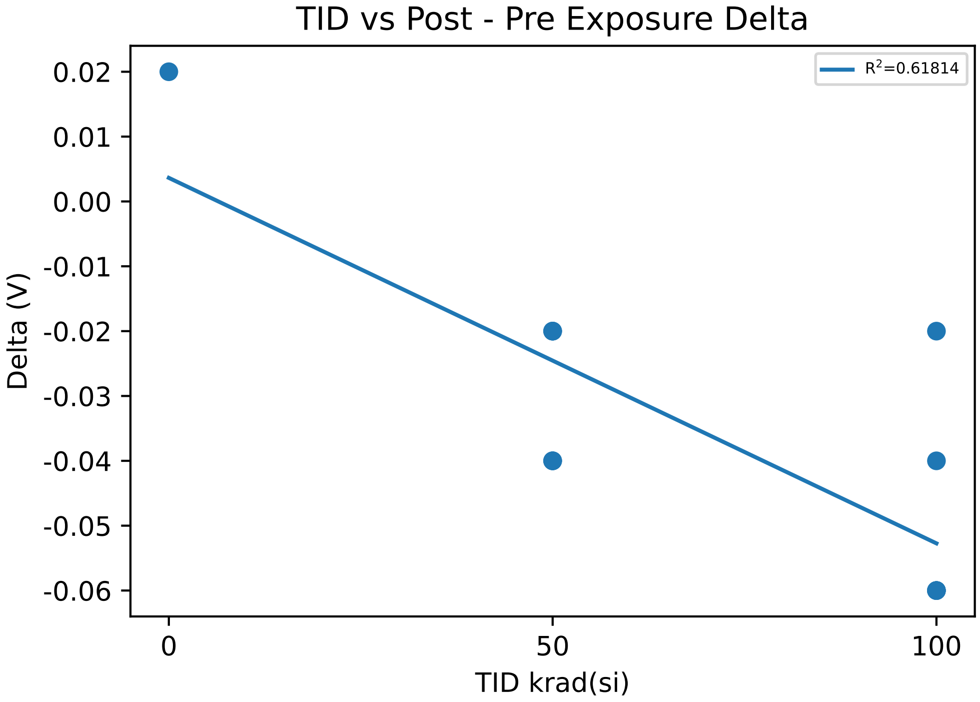
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.46	1.44	-0.02
60	50	Biased	1.46	1.44	-0.02
61	50	Biased	1.46	1.46	0
63	100	Biased	1.48	1.42	-0.06
64	100	Biased	1.46	1.42	-0.04
65	100	Biased	1.46	1.42	-0.04
66	50	Unbiased	1.48	1.44	-0.04
67	50	Unbiased	1.48	1.44	-0.04
68	50	Unbiased	1.48	1.46	-0.02
69	100	Unbiased	1.48	1.42	-0.06
70	100	Unbiased	1.48	1.44	-0.04
71	100	Unbiased	1.46	1.4	-0.06
72	0	Control	1.48	1.46	-0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48		1.46	1.46	1.46		-0.02	-0.02	-0.02	
50	1.46	1.47	1.48	0.010954	1.44	1.4467	1.46	0.010328	-0.04	-0.023333	0	0.015055
100	1.46	1.47	1.48	0.010954	1.4	1.42	1.44	0.012649	-0.06	-0.05	-0.04	0.010954

Device Test: 91.5 EN_HI Thresh Hysteresis VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

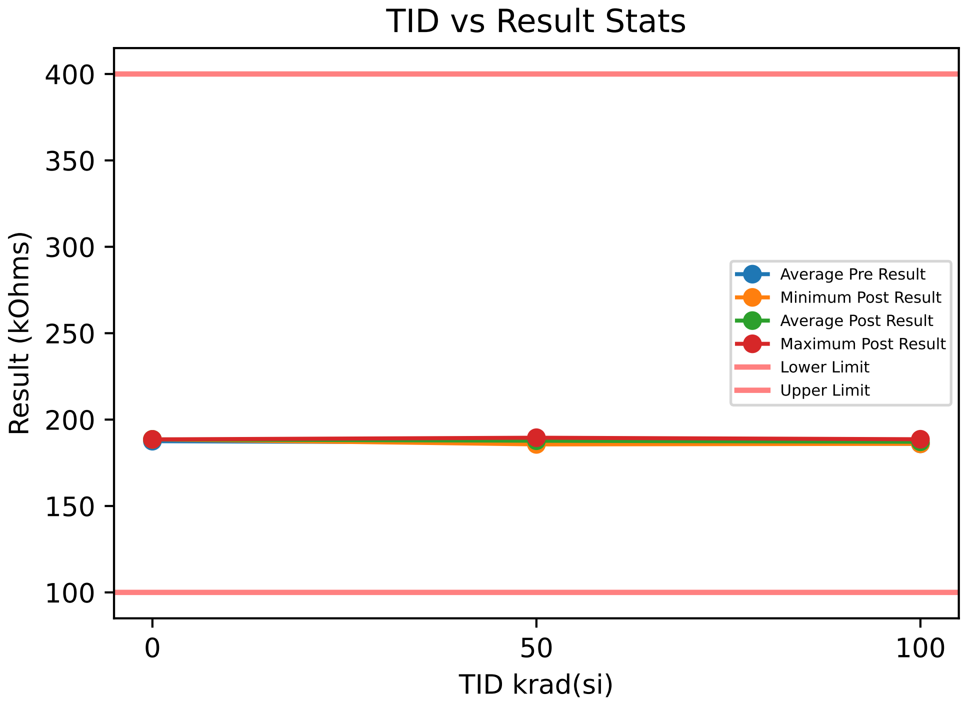
Test Results (Lower Limit = -0.05, Upper Limit = 1.5 (V))

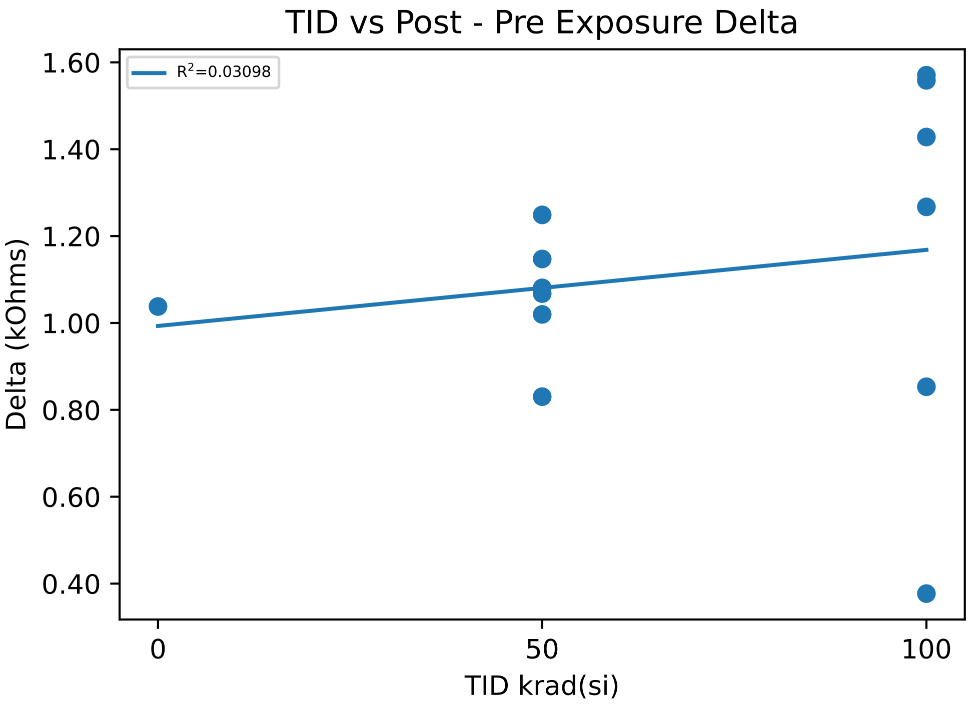
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.78	0.76	-0.02
60	50	Biased	0.78	0.74	-0.04
61	50	Biased	0.78	0.74	-0.04
63	100	Biased	0.76	0.72	-0.04
64	100	Biased	0.78	0.72	-0.06
65	100	Biased	0.78	0.72	-0.06
66	50	Unbiased	0.76	0.74	-0.02
67	50	Unbiased	0.76	0.74	-0.02
68	50	Unbiased	0.78	0.74	-0.04
69	100	Unbiased	0.76	0.74	-0.02
70	100	Unbiased	0.76	0.7	-0.06
71	100	Unbiased	0.78	0.72	-0.06
72	0	Control	0.76	0.78	0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.76	0.76	0.76		0.78	0.78	0.78		0.02	0.02	0.02	
50	0.76	0.77333	0.78	0.010328	0.74	0.74333	0.76	0.008165	-0.04	-0.03	-0.02	0.010954
100	0.76	0.77	0.78	0.010954	0.7	0.72	0.74	0.012649	-0.06	-0.05	-0.02	0.016733

Device Test: 91.6 PWM_LI Pull Down Resistance VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

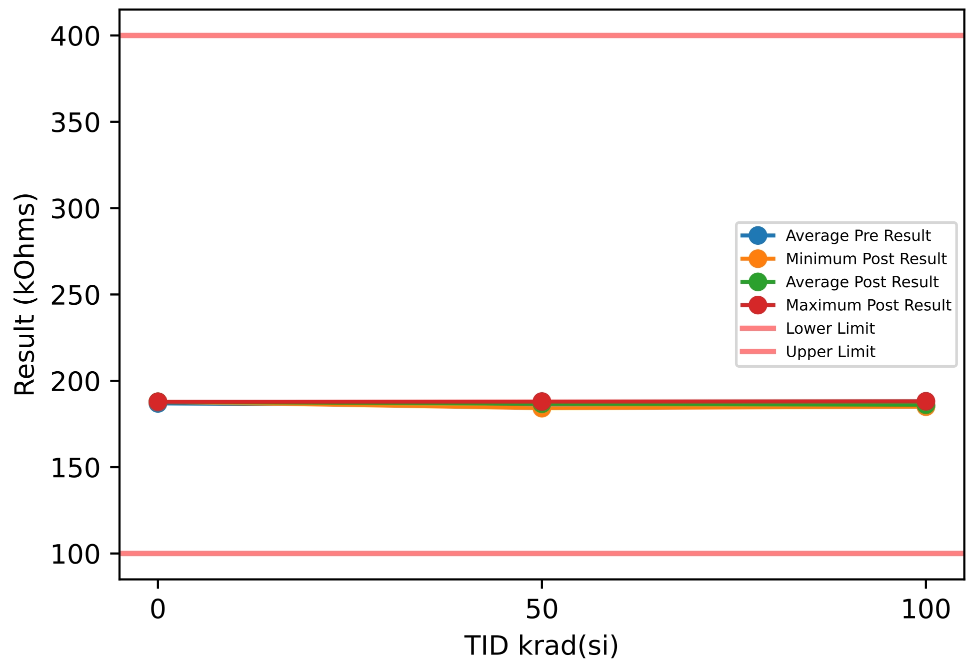
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kOhms))

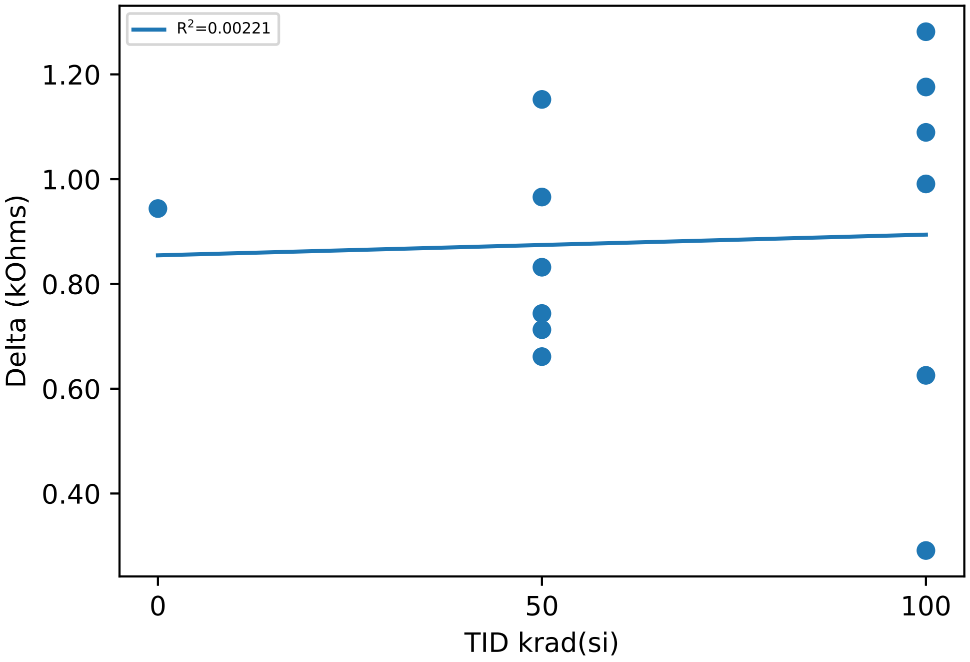
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	187.53	188.68	1.1473
60	50	Biased	188.5	189.52	1.0197
61	50	Biased	188.1	189.18	1.0809
63	100	Biased	186.91	188.34	1.4281
64	100	Biased	187.06	188.63	1.5704
65	100	Biased	185.68	187.24	1.5585
66	50	Unbiased	184.81	185.64	0.8304
67	50	Unbiased	186.57	187.64	1.0676
68	50	Unbiased	184.69	185.94	1.2488
69	100	Unbiased	185.74	186.6	0.8532
70	100	Unbiased	185.59	185.96	0.377
71	100	Unbiased	184.86	186.12	1.2673
72	0	Control	187.5	188.54	1.0379

Test Statistics (kOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	187.5	187.5	187.5		188.54	188.54	188.54		1.0379	1.0379	1.0379	
50	184.69	186.7	188.5	1.6425	185.64	187.77	189.52	1.6584	0.8304	1.0658	1.2488	0.13993
100	184.86	185.97	187.06	0.84702	185.96	187.15	188.63	1.1285	0.377	1.1758	1.5704	0.47251

Device Test: 91.7 EN_HI Pull Down Resistance VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

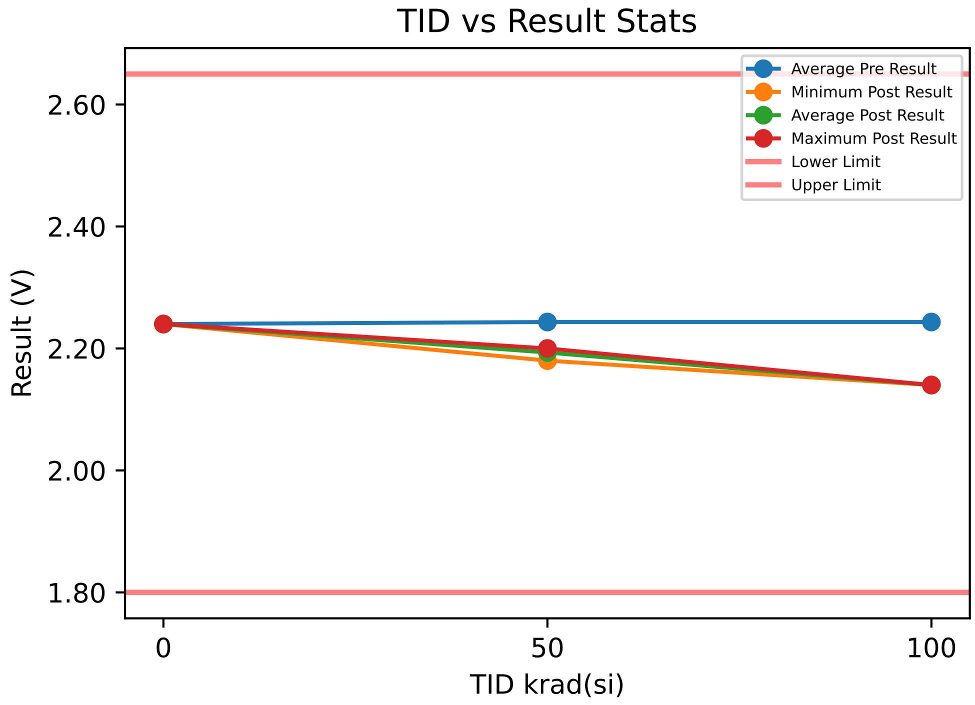
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kOhms))

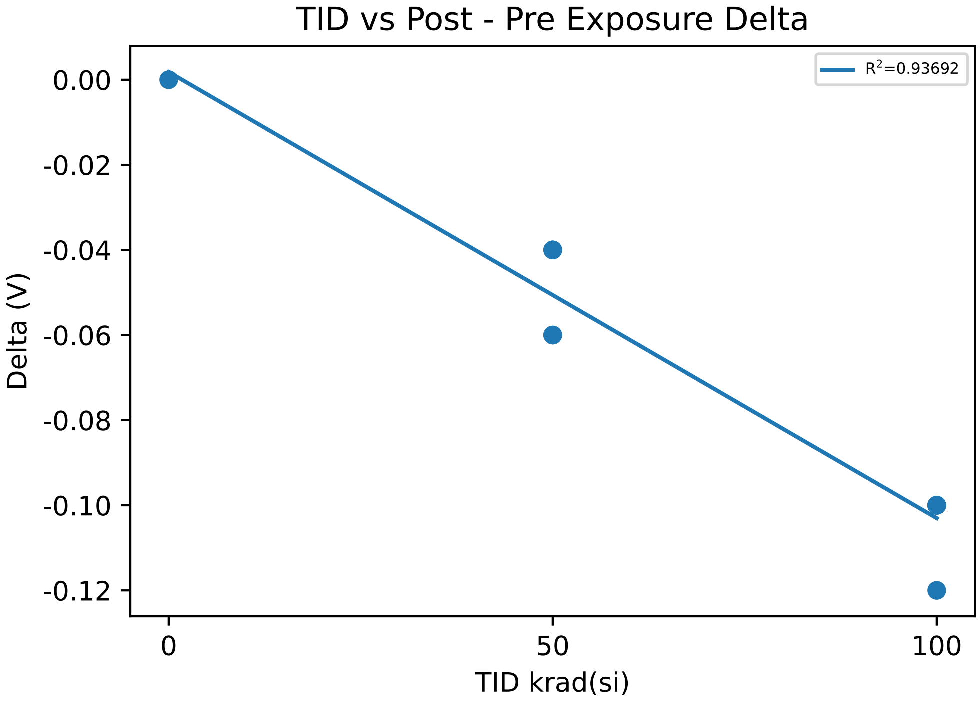
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	186.91	187.66	0.7436
60	50	Biased	186.86	187.83	0.9659
61	50	Biased	187.33	187.99	0.6613
63	100	Biased	185.68	186.68	0.9909
64	100	Biased	186.96	188.14	1.1759
65	100	Biased	185.17	186.45	1.2814
66	50	Unbiased	183.46	184.17	0.7127
67	50	Unbiased	186.41	187.24	0.8319
68	50	Unbiased	184.4	185.55	1.1522
69	100	Unbiased	184.42	185.04	0.6255
70	100	Unbiased	184.82	185.11	0.2912
71	100	Unbiased	184.34	185.43	1.0893
72	0	Control	186.92	187.86	0.9439

Test Statistics (kOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	186.92	186.92	186.92		187.86	187.86	187.86		0.9439	0.9439	0.9439	
50	183.46	185.89	187.33	1.5772	184.17	186.74	187.99	1.5377	0.6613	0.8446	1.1522	0.18476
100	184.34	185.23	186.96	0.98368	185.04	186.14	188.14	1.1957	0.2912	0.90903	1.2814	0.37714

Device Test: 92.0 PWM_LI Rise Thresh VIN_14V





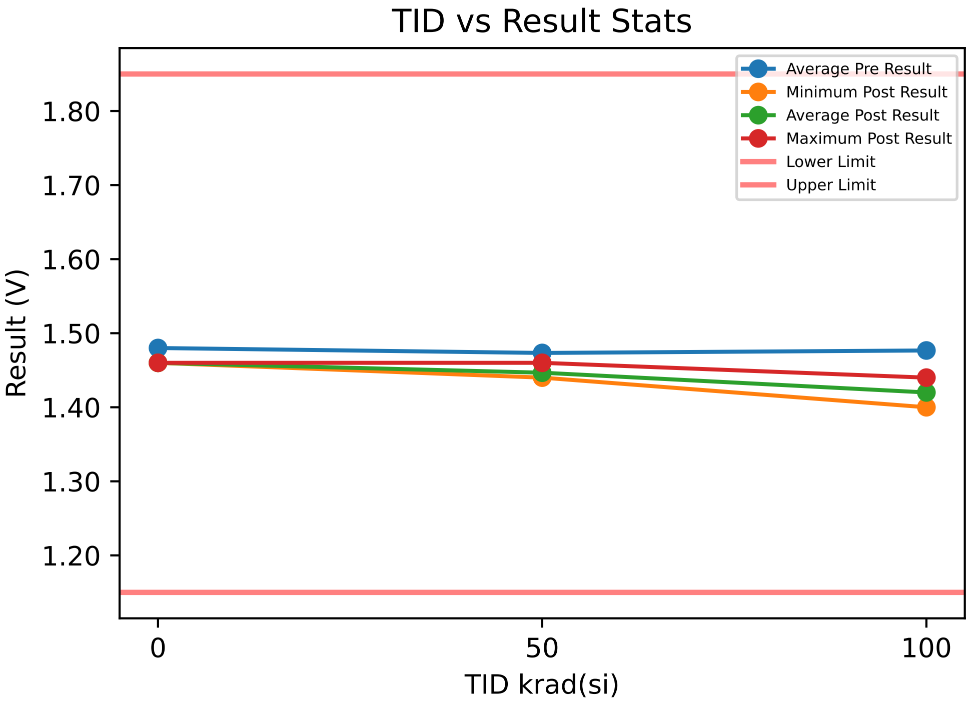
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

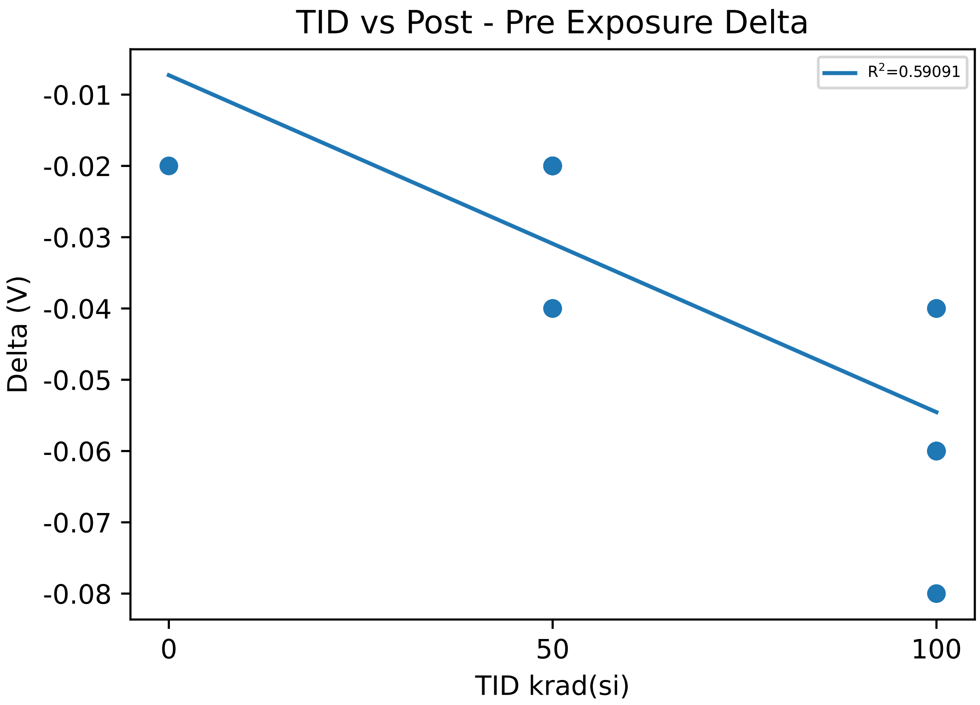
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.24	2.2	-0.04
60	50	Biased	2.24	2.18	-0.06
61	50	Biased	2.24	2.2	-0.04
63	100	Biased	2.24	2.14	-0.1
64	100	Biased	2.24	2.14	-0.1
65	100	Biased	2.24	2.14	-0.1
66	50	Unbiased	2.24	2.18	-0.06
67	50	Unbiased	2.24	2.2	-0.04
68	50	Unbiased	2.26	2.2	-0.06
69	100	Unbiased	2.26	2.14	-0.12
70	100	Unbiased	2.24	2.14	-0.1
71	100	Unbiased	2.24	2.14	-0.1
72	0	Control	2.24	2.24	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.24	2.24	2.24		2.24	2.24	2.24		0	0	0	
50	2.24	2.2433	2.26	0.008165	2.18	2.1933	2.2	0.010328	-0.06	-0.05	-0.04	0.010954
100	2.24	2.2433	2.26	0.008165	2.14	2.14	2.14	0	-0.12	-0.10333	-0.1	0.008165

Device Test: 92.1 PWM_LI Fall Thresh VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

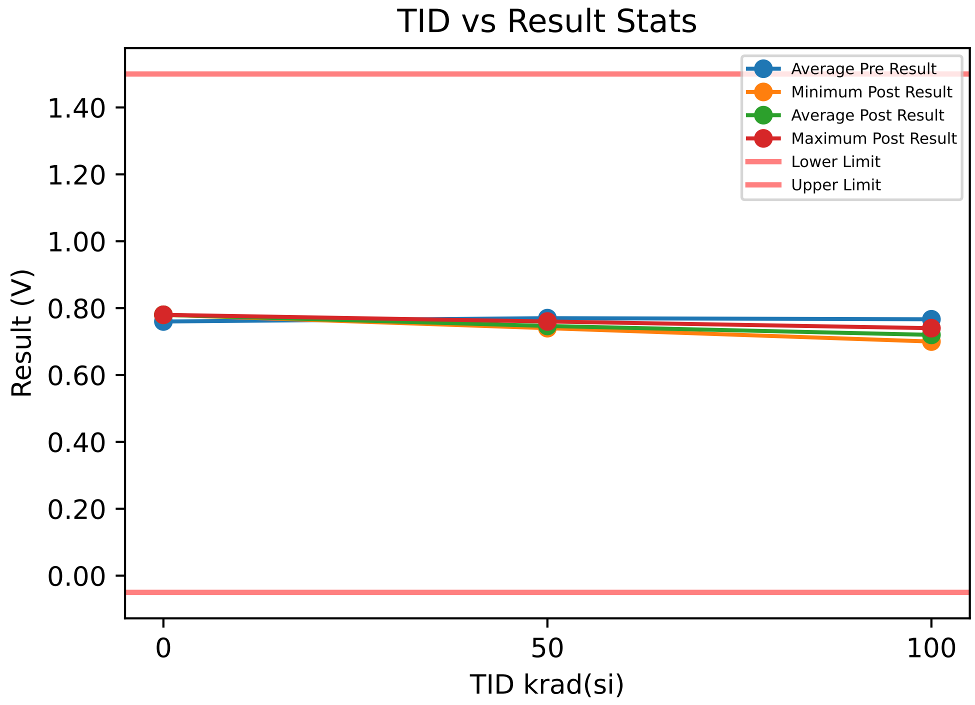
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

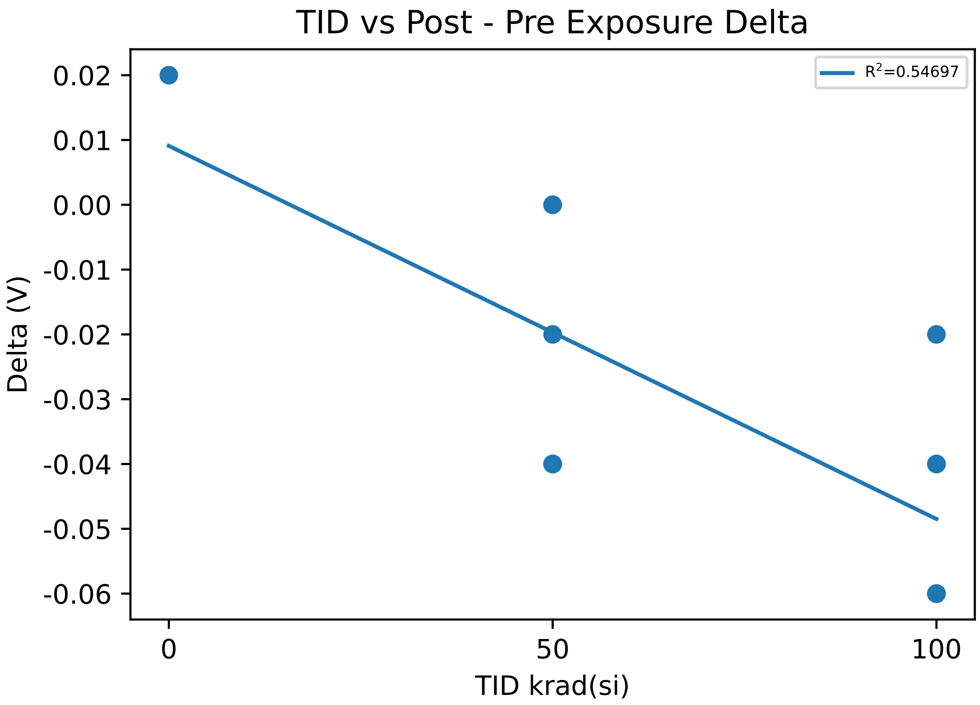
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.48	1.44	-0.04
60	50	Biased	1.46	1.44	-0.02
61	50	Biased	1.48	1.46	-0.02
63	100	Biased	1.48	1.42	-0.06
64	100	Biased	1.46	1.42	-0.04
65	100	Biased	1.48	1.44	-0.04
66	50	Unbiased	1.46	1.44	-0.02
67	50	Unbiased	1.48	1.44	-0.04
68	50	Unbiased	1.48	1.46	-0.02
69	100	Unbiased	1.48	1.42	-0.06
70	100	Unbiased	1.48	1.42	-0.06
71	100	Unbiased	1.48	1.4	-0.08
72	0	Control	1.48	1.46	-0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48		1.46	1.46	1.46		-0.02	-0.02	-0.02	
50	1.46	1.4733	1.48	0.010328	1.44	1.4467	1.46	0.010328	-0.04	-0.026667	-0.02	0.010328
100	1.46	1.4767	1.48	0.008165	1.4	1.42	1.44	0.012649	-0.08	-0.056667	-0.04	0.015055

Device Test: 92.2 PWM_LI Thresh Hysteresis VIN_14V





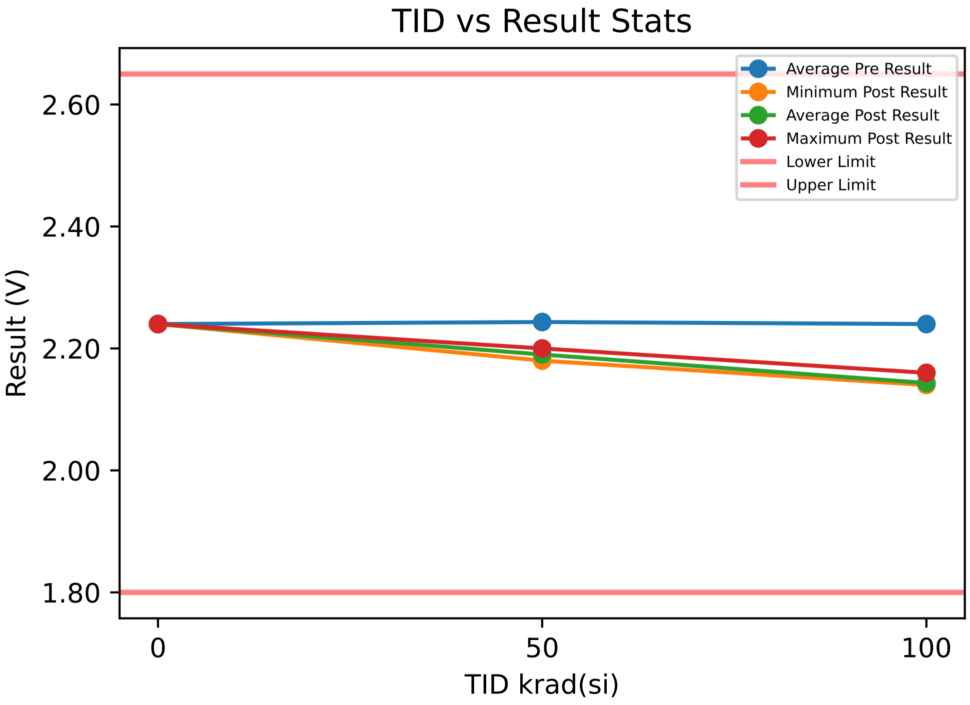
Test Results (Lower Limit = -0.05, Upper Limit = 1.5 (V))

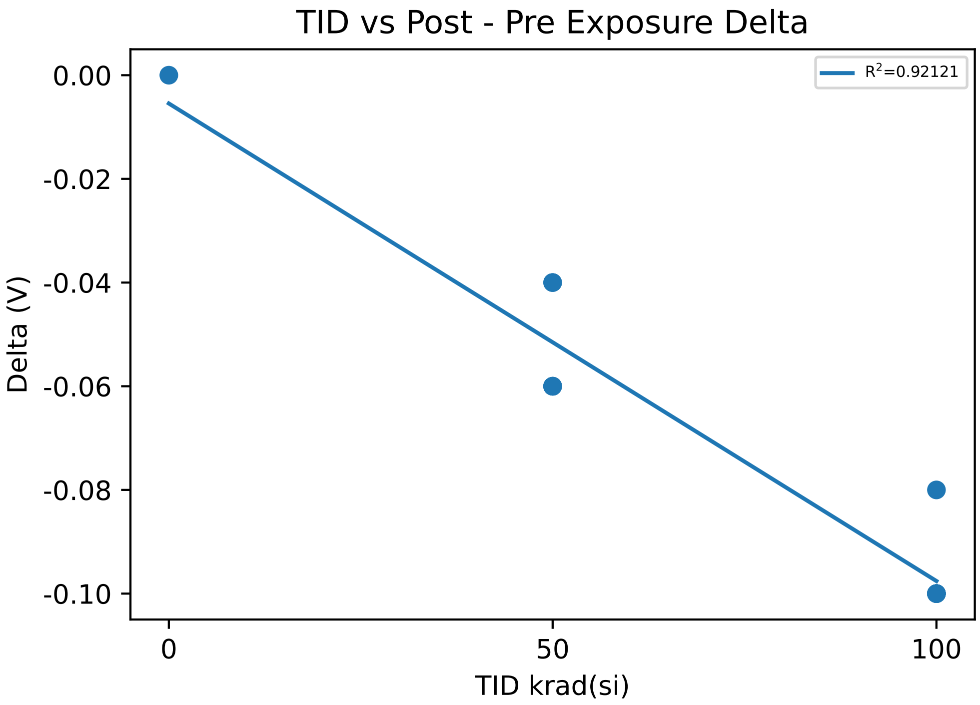
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.76	0.76	0
60	50	Biased	0.78	0.74	-0.04
61	50	Biased	0.76	0.74	-0.02
63	100	Biased	0.76	0.72	-0.04
64	100	Biased	0.78	0.72	-0.06
65	100	Biased	0.76	0.7	-0.06
66	50	Unbiased	0.78	0.74	-0.04
67	50	Unbiased	0.76	0.76	0
68	50	Unbiased	0.78	0.74	-0.04
69	100	Unbiased	0.78	0.72	-0.06
70	100	Unbiased	0.76	0.72	-0.04
71	100	Unbiased	0.76	0.74	-0.02
72	0	Control	0.76	0.78	0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.76	0.76	0.76		0.78	0.78	0.78		0.02	0.02	0.02	
50	0.76	0.77	0.78	0.010954	0.74	0.74667	0.76	0.010328	-0.04	-0.023333	0	0.019664
100	0.76	0.76667	0.78	0.010328	0.7	0.72	0.74	0.012649	-0.06	-0.046667	-0.02	0.01633

Device Test: 92.3 EN_HI Rise Thresh VIN_14V





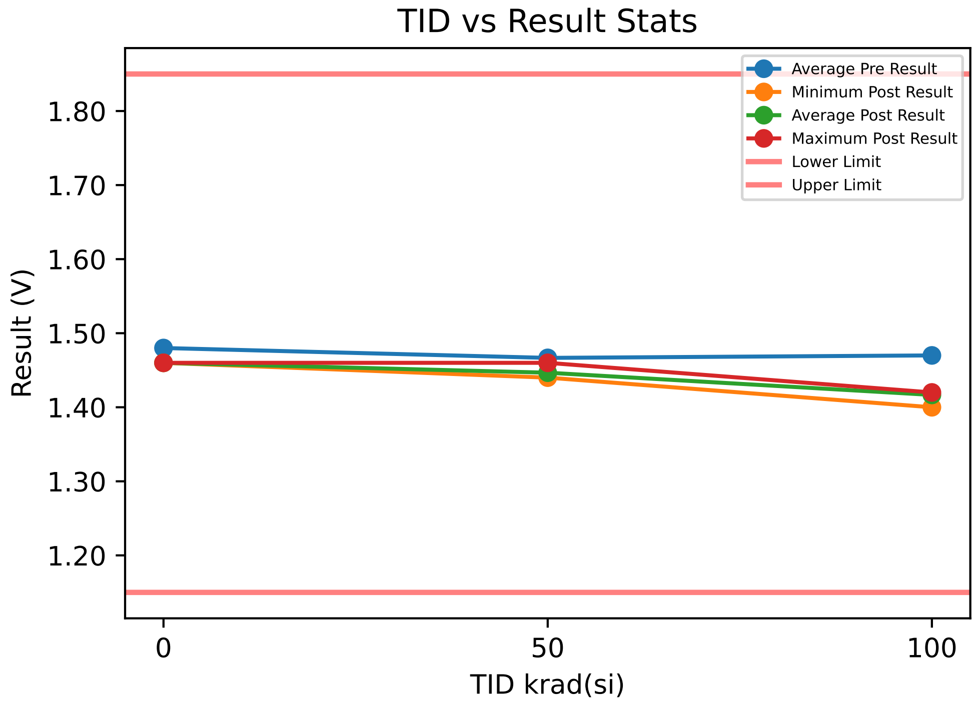
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

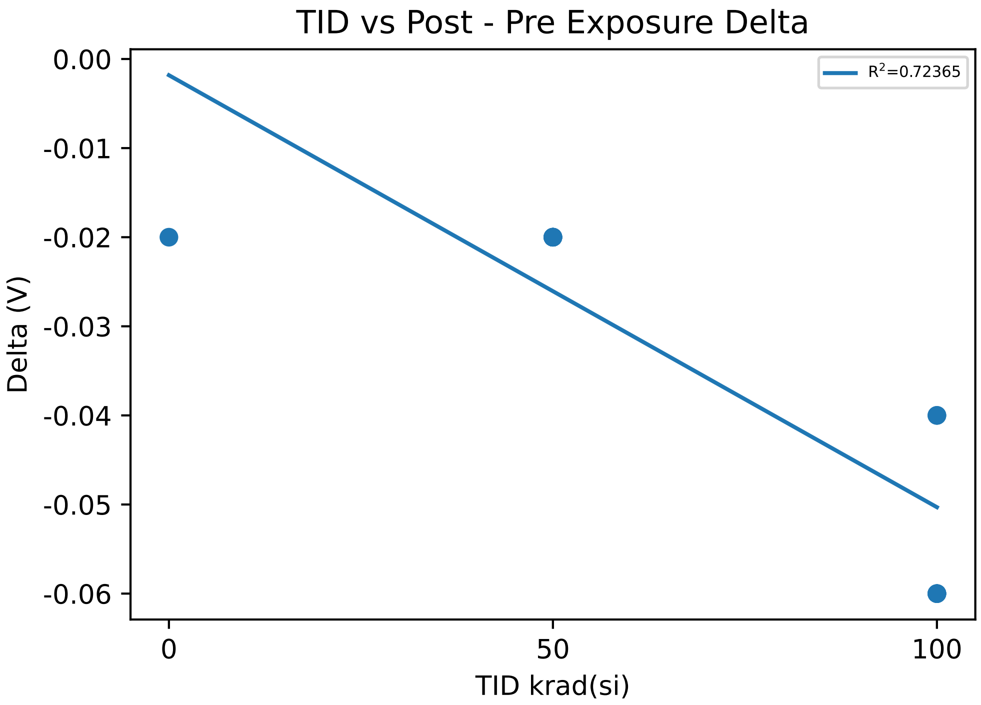
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	2.24	2.2	-0.04
60	50	Biased	2.24	2.18	-0.06
61	50	Biased	2.24	2.2	-0.04
63	100	Biased	2.24	2.14	-0.1
64	100	Biased	2.24	2.14	-0.1
65	100	Biased	2.24	2.14	-0.1
66	50	Unbiased	2.24	2.18	-0.06
67	50	Unbiased	2.24	2.18	-0.06
68	50	Unbiased	2.26	2.2	-0.06
69	100	Unbiased	2.24	2.16	-0.08
70	100	Unbiased	2.24	2.14	-0.1
71	100	Unbiased	2.24	2.14	-0.1
72	0	Control	2.24	2.24	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.24	2.24	2.24		2.24	2.24	2.24		0	0	0	
50	2.24	2.2433	2.26	0.008165	2.18	2.19	2.2	0.010954	-0.06	-0.053333	-0.04	0.010328
100	2.24	2.24	2.24	0	2.14	2.1433	2.16	0.008165	-0.1	-0.096667	-0.08	0.008165

Device Test: 92.4 EN_HI Fall Thresh VIN_14V





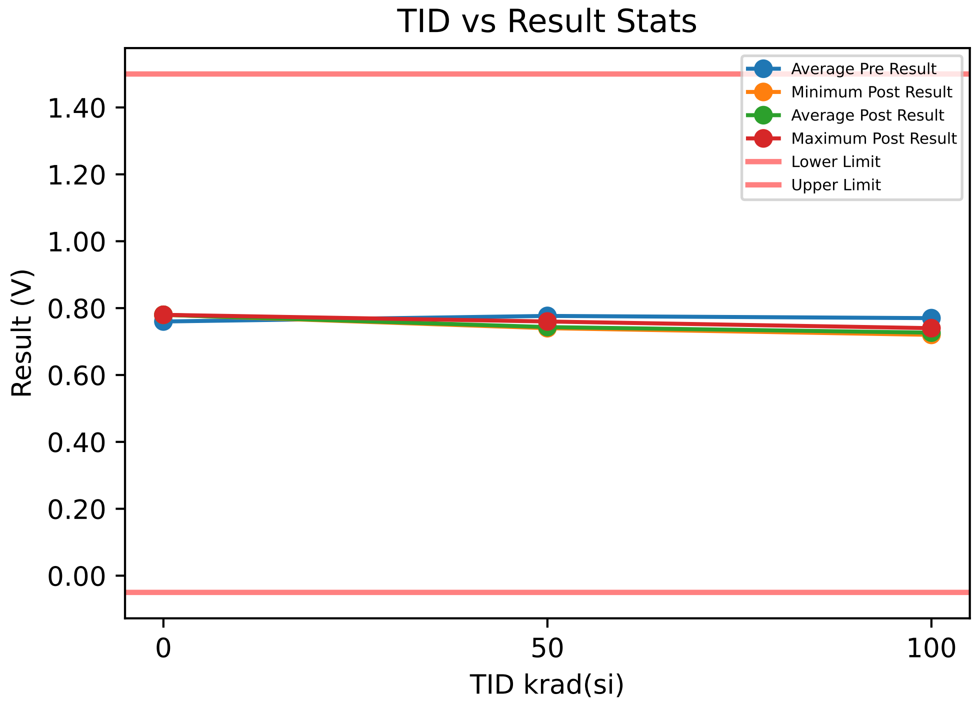
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

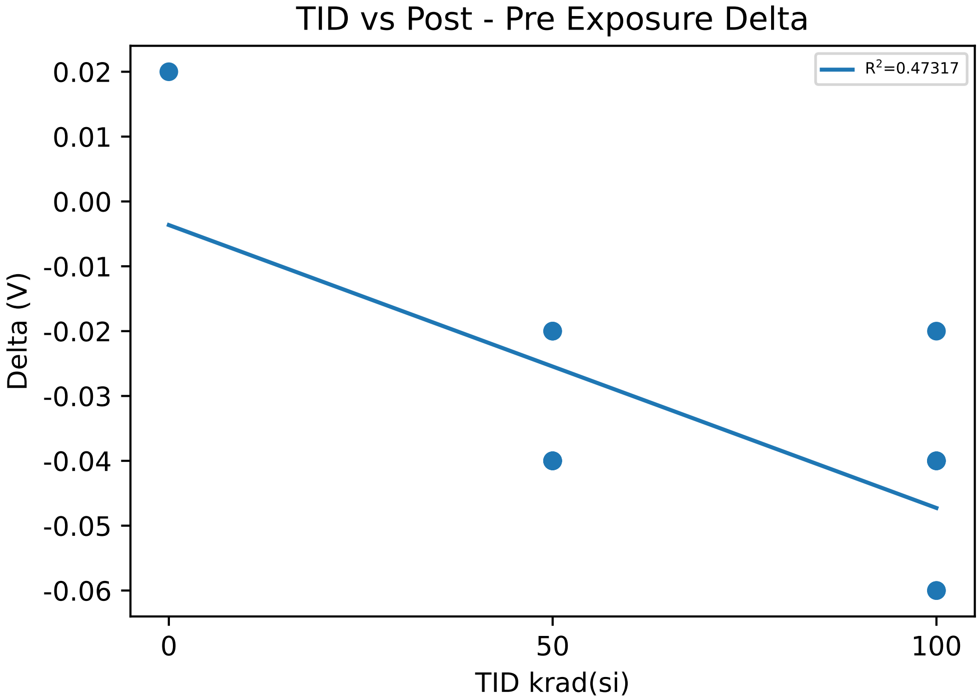
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	1.46	1.44	-0.02
60	50	Biased	1.46	1.44	-0.02
61	50	Biased	1.48	1.46	-0.02
63	100	Biased	1.48	1.42	-0.06
64	100	Biased	1.46	1.42	-0.04
65	100	Biased	1.46	1.42	-0.04
66	50	Unbiased	1.46	1.44	-0.02
67	50	Unbiased	1.46	1.44	-0.02
68	50	Unbiased	1.48	1.46	-0.02
69	100	Unbiased	1.48	1.42	-0.06
70	100	Unbiased	1.48	1.42	-0.06
71	100	Unbiased	1.46	1.4	-0.06
72	0	Control	1.48	1.46	-0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48		1.46	1.46	1.46		-0.02	-0.02	-0.02	
50	1.46	1.4667	1.48	0.010328	1.44	1.4467	1.46	0.010328	-0.02	-0.02	-0.02	0
100	1.46	1.47	1.48	0.010954	1.4	1.4167	1.42	0.008165	-0.06	-0.053333	-0.04	0.010328

Device Test: 92.5 EN_HI Thresh Hysteresis VIN_14V





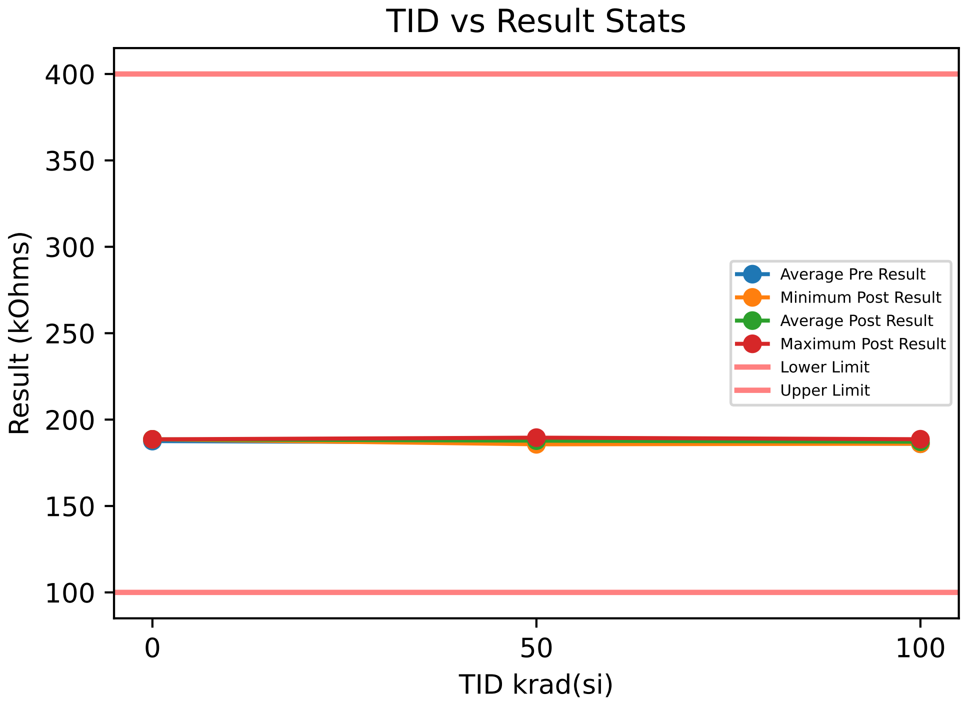
Test Results (Lower Limit = -0.05, Upper Limit = 1.5 (V))

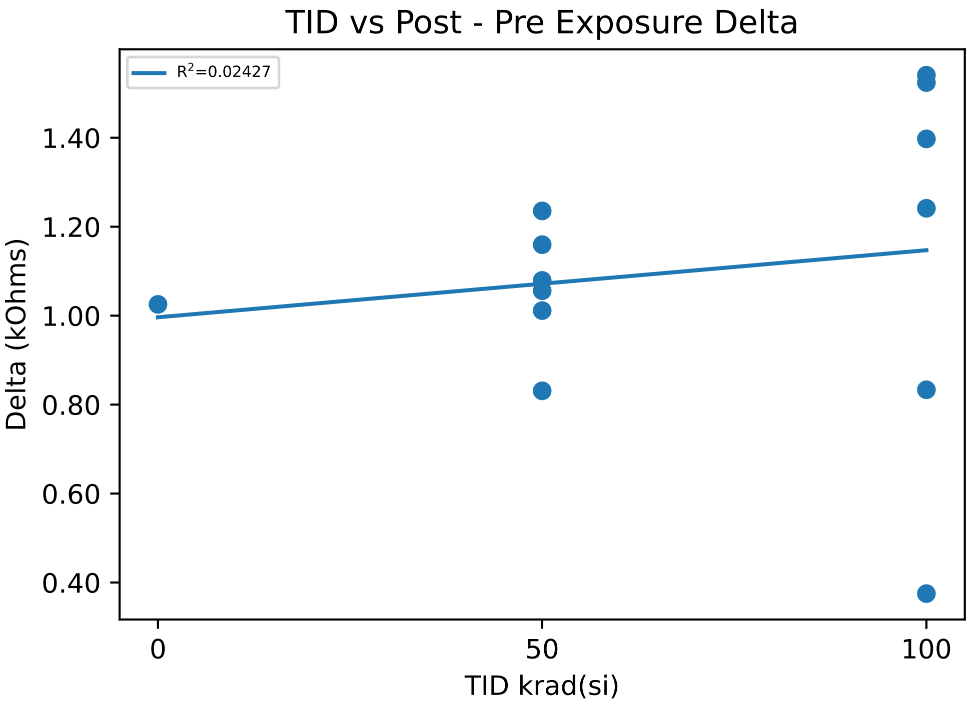
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	0.78	0.76	-0.02
60	50	Biased	0.78	0.74	-0.04
61	50	Biased	0.76	0.74	-0.02
63	100	Biased	0.76	0.72	-0.04
64	100	Biased	0.78	0.72	-0.06
65	100	Biased	0.78	0.72	-0.06
66	50	Unbiased	0.78	0.74	-0.04
67	50	Unbiased	0.78	0.74	-0.04
68	50	Unbiased	0.78	0.74	-0.04
69	100	Unbiased	0.76	0.74	-0.02
70	100	Unbiased	0.76	0.72	-0.04
71	100	Unbiased	0.78	0.74	-0.04
72	0	Control	0.76	0.78	0.02

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.76	0.76	0.76		0.78	0.78	0.78		0.02	0.02	0.02	
50	0.76	0.77667	0.78	0.008165	0.74	0.74333	0.76	0.008165	-0.04	-0.033333	-0.02	0.010328
100	0.76	0.77	0.78	0.010954	0.72	0.72667	0.74	0.010328	-0.06	-0.043333	-0.02	0.015055

Device Test: 92.6 PWM_LI Pull Down Resistance VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

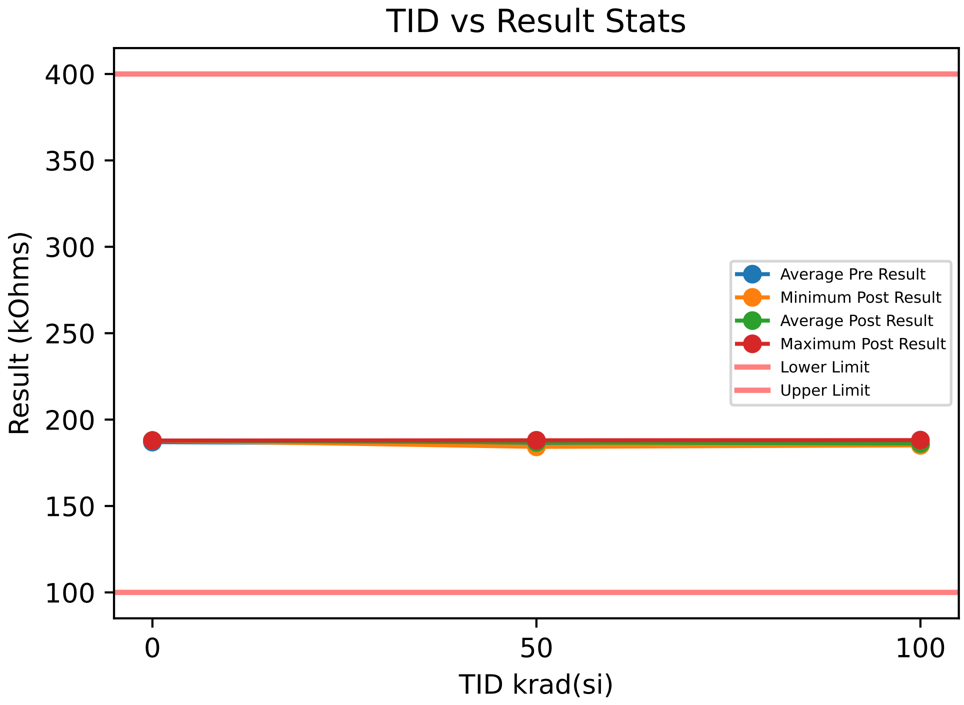
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kOhms))

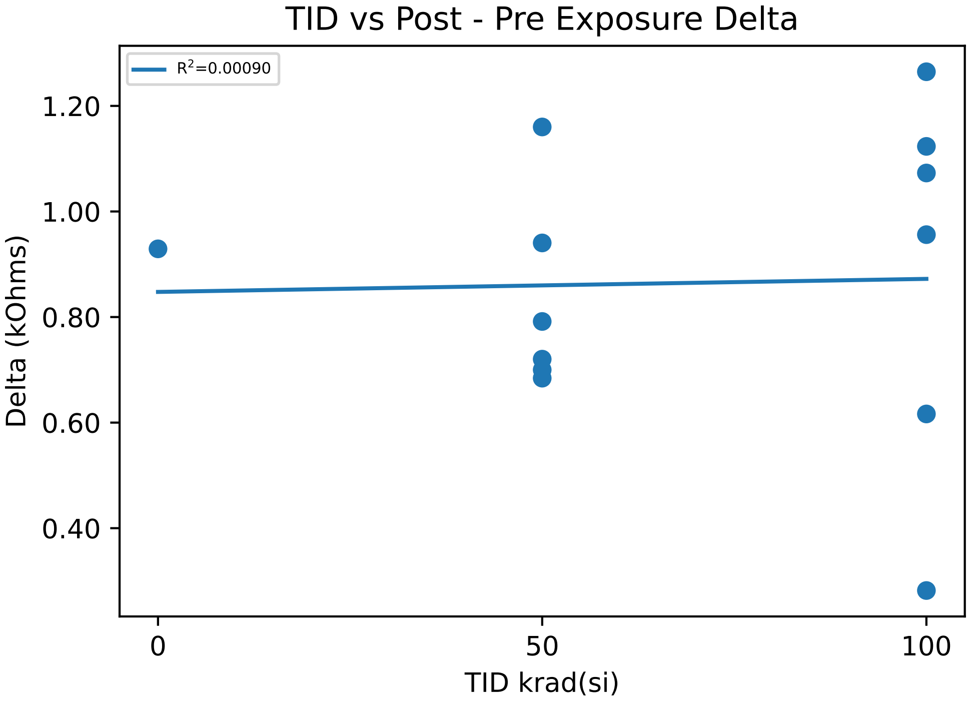
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	187.56	188.72	1.1597
60	50	Biased	188.54	189.55	1.0114
61	50	Biased	188.15	189.23	1.0793
63	100	Biased	186.96	188.36	1.3975
64	100	Biased	187.11	188.65	1.5407
65	100	Biased	185.74	187.26	1.5241
66	50	Unbiased	184.86	185.7	0.831
67	50	Unbiased	186.6	187.66	1.0561
68	50	Unbiased	184.73	185.97	1.2355
69	100	Unbiased	185.79	186.63	0.8334
70	100	Unbiased	185.63	186.01	0.3751
71	100	Unbiased	184.9	186.14	1.2415
72	0	Control	187.56	188.58	1.0254

Test Statistics (kOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	187.56	187.56	187.56		188.58	188.58	188.58		1.0254	1.0254	1.0254	
50	184.73	186.74	188.54	1.6422	185.7	187.8	189.55	1.6601	0.831	1.0622	1.2355	0.13849
100	184.9	186.02	187.11	0.84885	186.01	187.18	188.65	1.1232	0.3751	1.152	1.5407	0.46107

Device Test: 92.7 EN_HI Pull Down Resistance VIN_14V





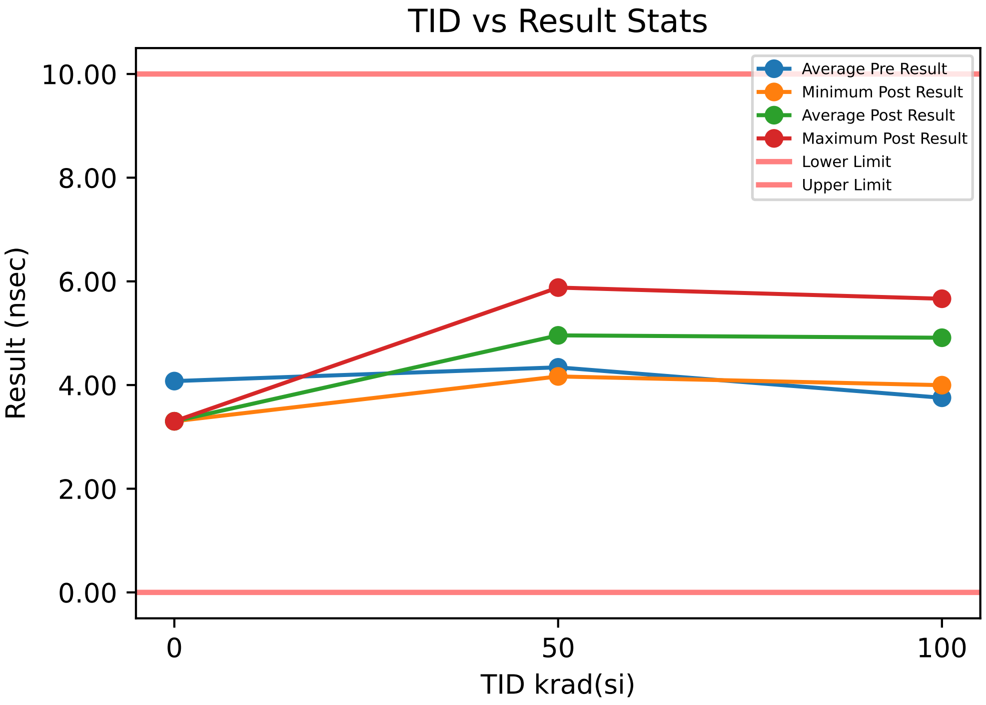
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kOhms))

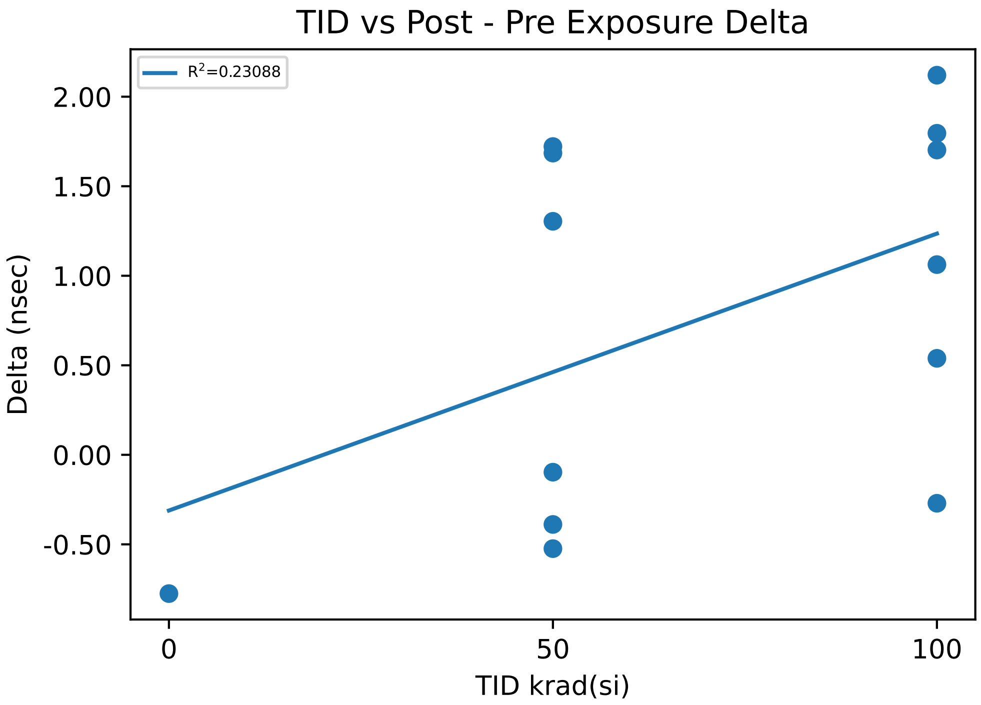
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	186.99	187.69	0.7
60	50	Biased	186.9	187.84	0.9404
61	50	Biased	187.35	188.03	0.6842
63	100	Biased	185.72	186.68	0.9561
64	100	Biased	187.01	188.13	1.1233
65	100	Biased	185.2	186.46	1.2647
66	50	Unbiased	183.5	184.22	0.7202
67	50	Unbiased	186.46	187.25	0.7916
68	50	Unbiased	184.45	185.61	1.1601
69	100	Unbiased	184.45	185.07	0.6164
70	100	Unbiased	184.86	185.14	0.2819
71	100	Unbiased	184.38	185.45	1.0729
72	0	Control	186.96	187.89	0.9292

Test Statistics (kOhms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	186.96	186.96	186.96		187.89	187.89	187.89		0.9292	0.9292	0.9292	
50	183.5	185.94	187.35	1.5784	184.22	186.77	188.03	1.5275	0.6842	0.83275	1.1601	0.1859
100	184.38	185.27	187.01	0.98776	185.07	186.16	188.13	1.1823	0.2819	0.88588	1.2647	0.36802

Device Test: 95.0 DLH Dead Time Min 500kHz VIN_10V





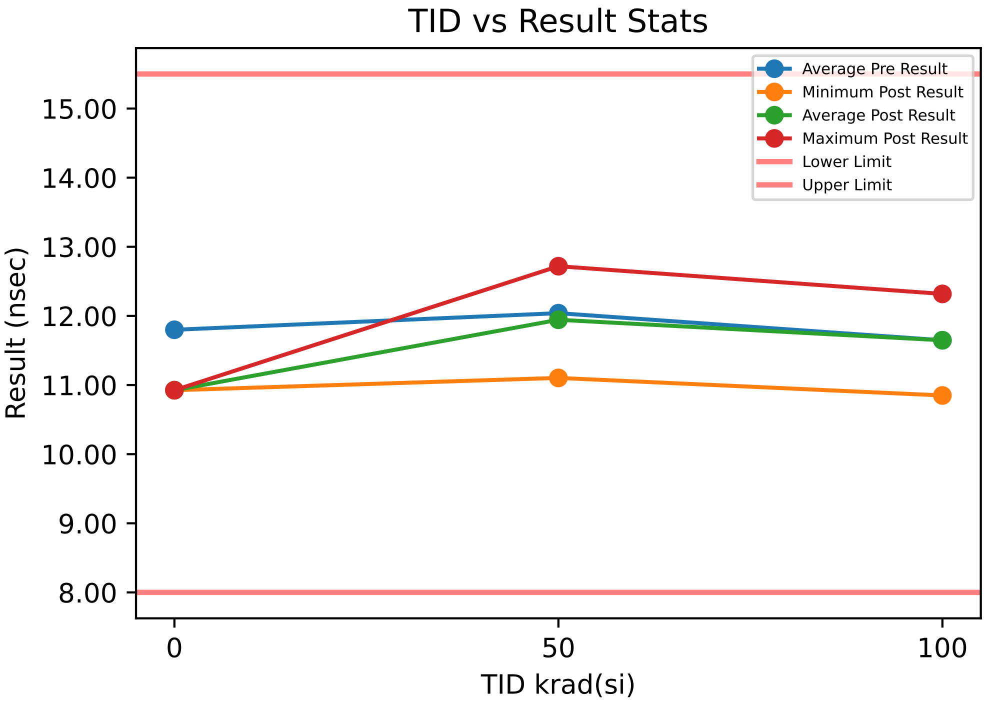
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

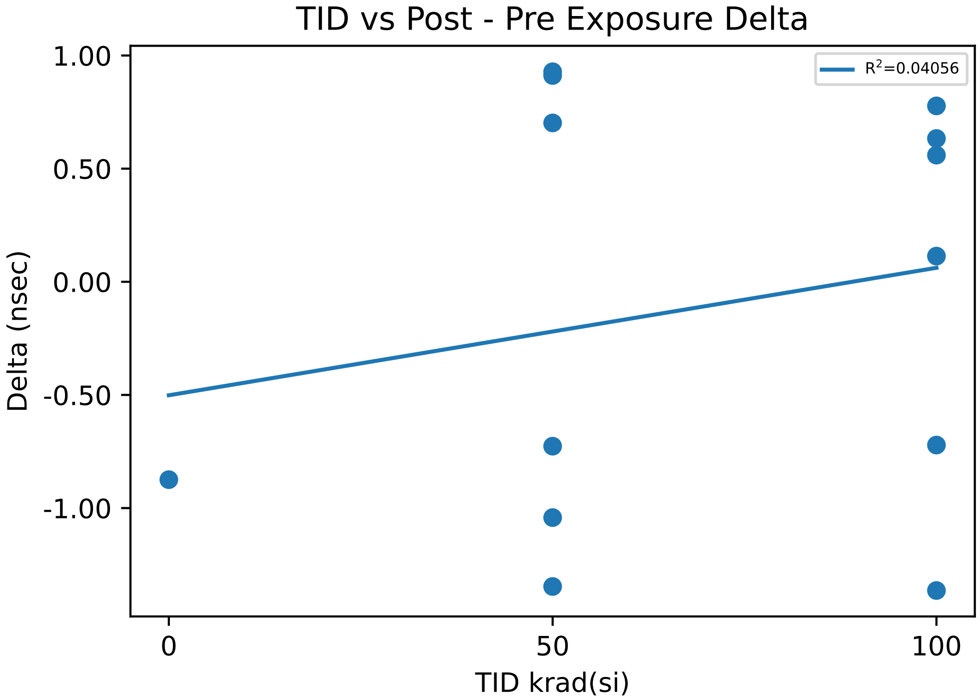
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.1585	5.8802	1.7217
60	50	Biased	4.9465	4.4225	-0.524
61	50	Biased	4.4141	5.7182	1.3041
63	100	Biased	3.8686	5.6644	1.7958
64	100	Biased	4.5013	5.5636	1.0623
65	100	Biased	3.5832	4.1221	0.5389
66	50	Unbiased	4.5548	4.1659	-0.3889
67	50	Unbiased	3.2636	4.9487	1.6851
68	50	Unbiased	4.7109	4.6139	-0.097
69	100	Unbiased	3.6781	5.3804	1.7023
70	100	Unbiased	4.2681	3.9975	-0.2706
71	100	Unbiased	2.6272	4.7473	2.1201
72	0	Control	4.0762	3.3011	-0.7751

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0762	4.0762	4.0762		3.3011	3.3011	3.3011		-0.7751	-0.7751	-0.7751	
50	3.2636	4.3414	4.9465	0.59137	4.1659	4.9582	5.8802	0.70157	-0.524	0.61683	1.7217	1.0637
100	2.6272	3.7544	4.5013	0.65429	3.9975	4.9125	5.6644	0.7345	-0.2706	1.1581	2.1201	0.90134

Device Test: 95.1 DLH Dead Time Small 500kHz VIN_10V





Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

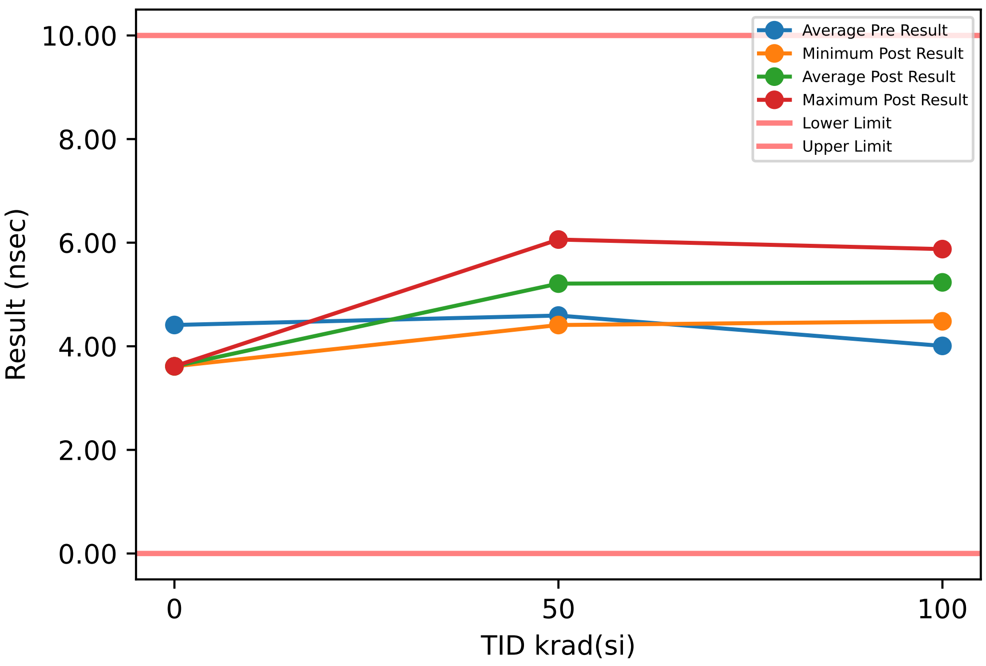
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	11.775	12.687	0.9117
60	50	Biased	12.45	11.103	-1.3465
61	50	Biased	12.017	12.719	0.702
63	100	Biased	11.53	12.307	0.7773
64	100	Biased	11.992	12.105	0.1135
65	100	Biased	11.674	10.953	-0.7215
66	50	Unbiased	12.348	11.306	-1.042
67	50	Unbiased	11.153	12.081	0.9282
68	50	Unbiased	12.495	11.769	-0.7265
69	100	Unbiased	11.759	12.319	0.5597
70	100	Unbiased	12.213	10.849	-1.3643
71	100	Unbiased	10.72	11.353	0.6333
72	0	Control	11.8	10.925	-0.8744

Test Statistics (nsec)

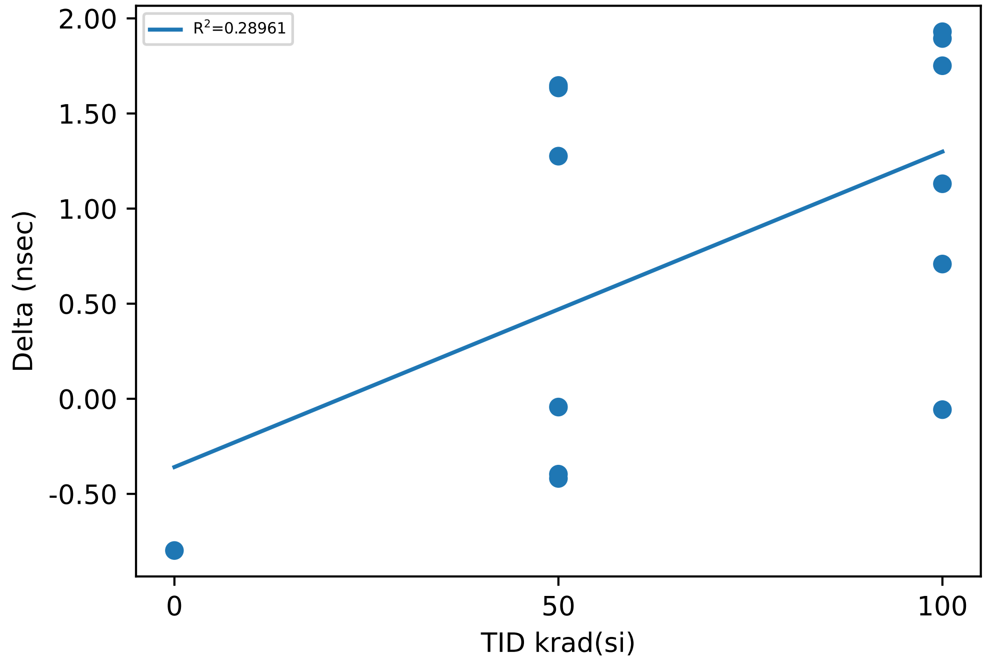
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.8	11.8	11.8		10.925	10.925	10.925		-0.8744	-0.8744	-0.8744	
50	11.153	12.04	12.495	0.51519	11.103	11.944	12.719	0.68056	-1.3465	-0.095517	0.9282	1.0543
100	10.72	11.648	12.213	0.51509	10.849	11.648	12.319	0.67851	-1.3643	-0.00033333	0.7773	0.86178

Device Test: 95.10 DLH Dead Time Min 2MHz VIN_10V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



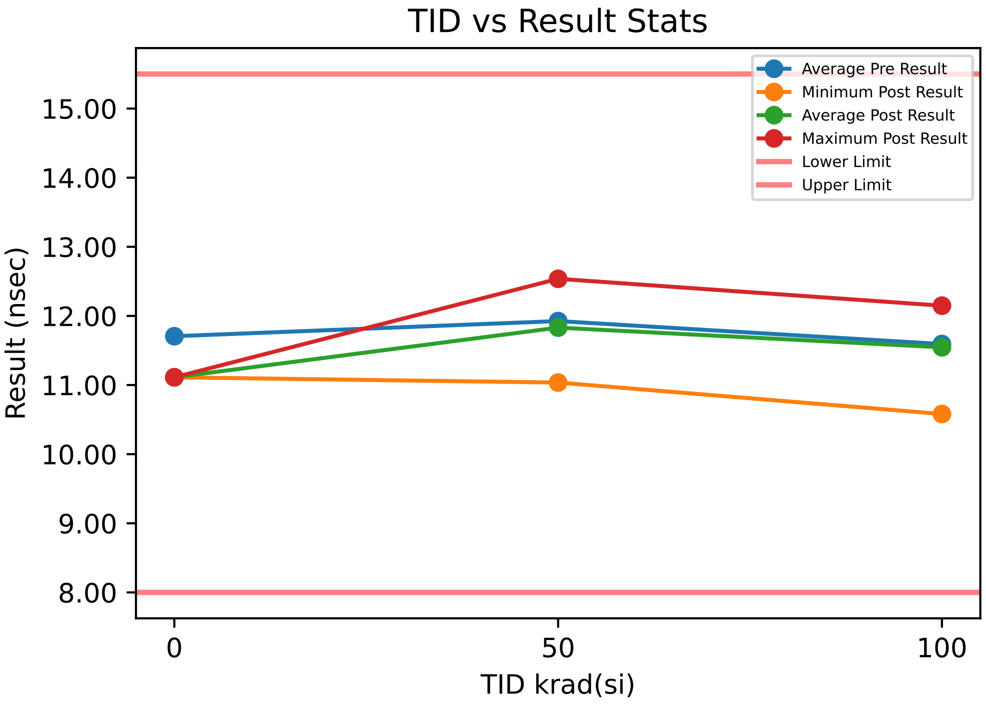
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

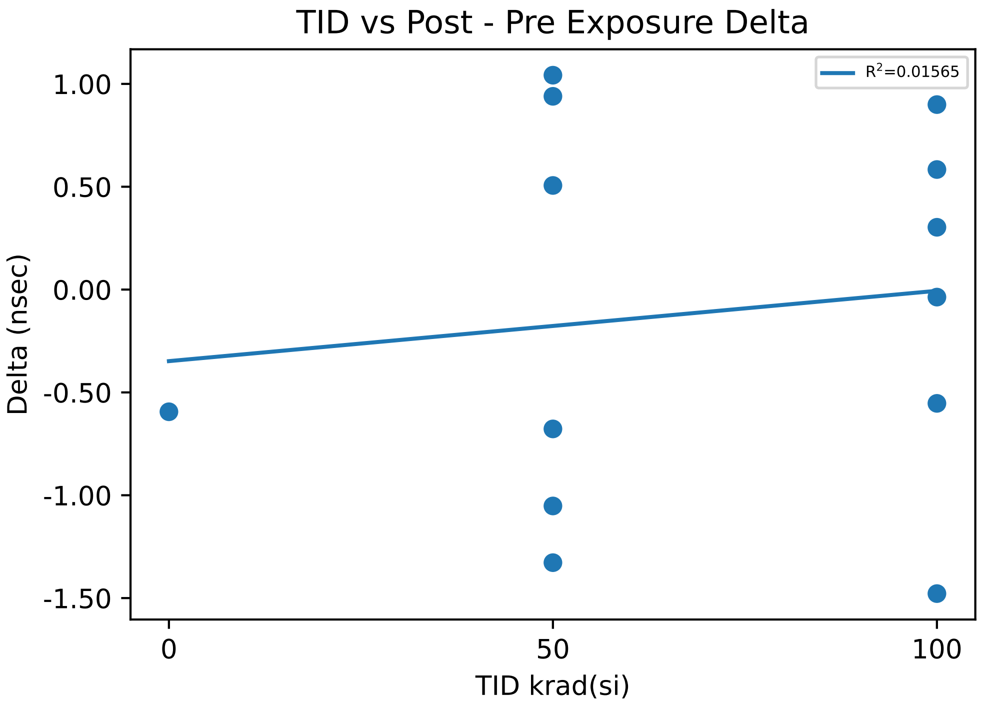
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.4262	6.0606	1.6344
60	50	Biased	5.1546	4.7358	-0.4188
61	50	Biased	4.6418	5.9174	1.2756
63	100	Biased	4.0924	5.8434	1.751
64	100	Biased	4.7453	5.8758	1.1305
65	100	Biased	3.8519	4.5603	0.7084
66	50	Unbiased	4.8066	4.4103	-0.3963
67	50	Unbiased	3.5671	5.2144	1.6473
68	50	Unbiased	4.9645	4.921	-0.0435
69	100	Unbiased	3.8807	5.7749	1.8942
70	100	Unbiased	4.5391	4.482	-0.0571
71	100	Unbiased	2.9362	4.866	1.9298
72	0	Control	4.4111	3.6134	-0.7977

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4111	4.4111	4.4111		3.6134	3.6134	3.6134		-0.7977	-0.7977	-0.7977	
50	3.5671	4.5935	5.1546	0.56244	4.4103	5.2099	6.0606	0.65907	-0.4188	0.61645	1.6473	1.0066
100	2.9362	4.0076	4.7453	0.63594	4.482	5.2337	5.8758	0.66793	-0.0571	1.2261	1.9298	0.79257

Device Test: 95.11 DLH Dead Time Small 2MHz VIN_10V





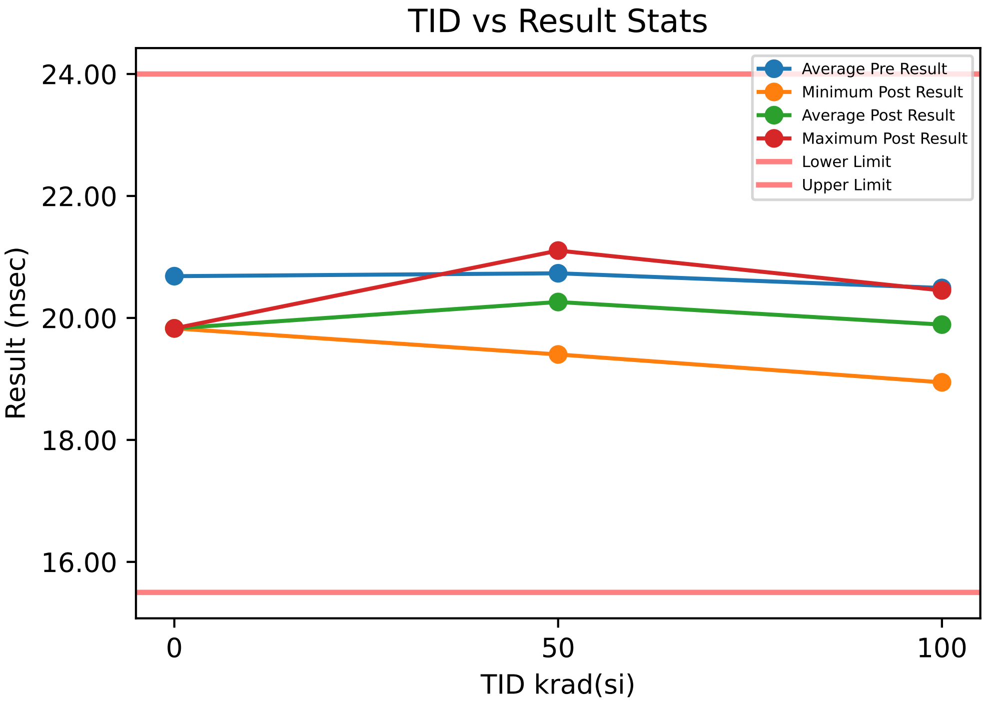
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

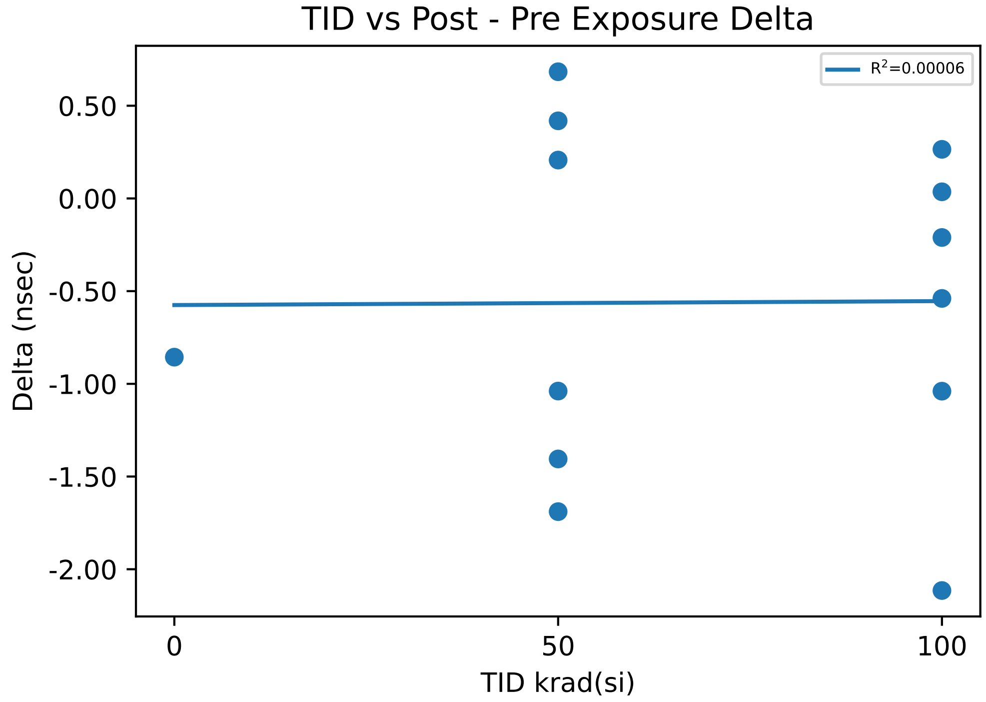
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	11.597	12.537	0.9396
60	50	Biased	12.364	11.036	-1.3278
61	50	Biased	11.856	12.362	0.5062
63	100	Biased	11.565	12.148	0.5837
64	100	Biased	12.073	12.037	-0.0366
65	100	Biased	11.619	11.065	-0.5533
66	50	Unbiased	12.252	11.2	-1.0521
67	50	Unbiased	11.084	12.126	1.0423
68	50	Unbiased	12.4	11.723	-0.6775
69	100	Unbiased	11.643	11.946	0.3029
70	100	Unbiased	12.059	10.581	-1.4782
71	100	Unbiased	10.6	11.5	0.8994
72	0	Control	11.706	11.112	-0.5941

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.706	11.706	11.706		11.112	11.112	11.112		-0.5941	-0.5941	-0.5941	
50	11.084	11.925	12.4	0.5187	11.036	11.831	12.537	0.61798	-1.3278	-0.094883	1.0423	1.0489
100	10.6	11.593	12.073	0.53618	10.581	11.546	12.148	0.62086	-1.4782	-0.047017	0.8994	0.86263

Device Test: 95.12 DLH Dead Time Mid 2MHz VIN_10V





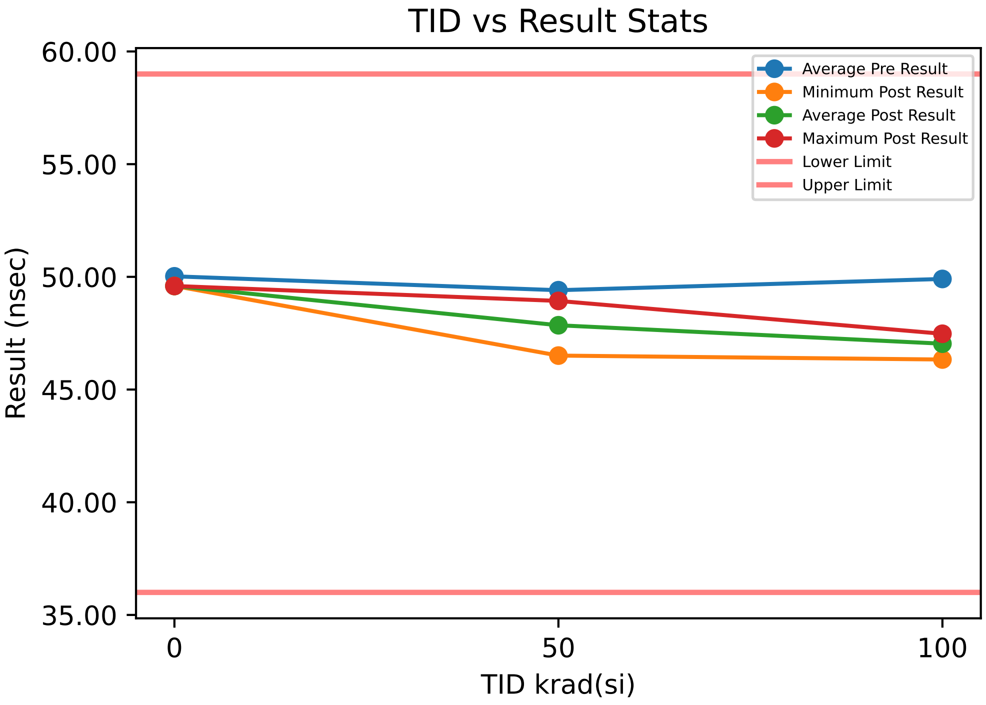
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

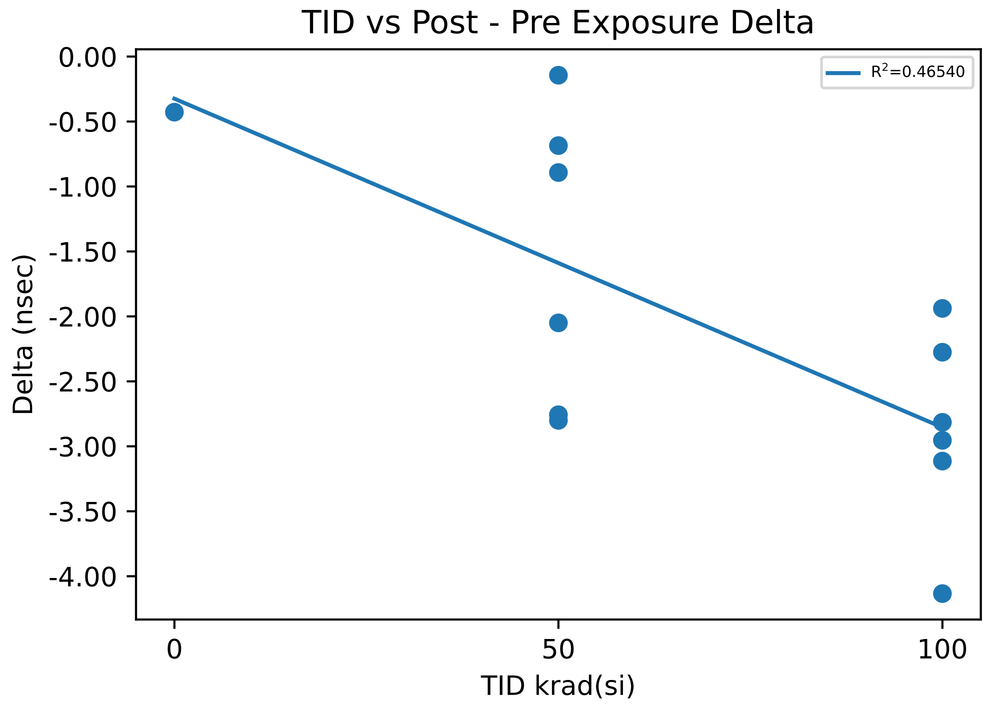
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	20.422	21.105	0.6833
60	50	Biased	21.091	19.401	-1.6893
61	50	Biased	20.599	20.805	0.207
63	100	Biased	20.187	20.451	0.2648
64	100	Biased	20.764	20.225	-0.5393
65	100	Biased	20.703	19.664	-1.0396
66	50	Unbiased	21.15	19.745	-1.4052
67	50	Unbiased	20.058	20.477	0.4186
68	50	Unbiased	21.075	20.036	-1.039
69	100	Unbiased	20.617	20.406	-0.2107
70	100	Unbiased	21.059	18.944	-2.1148
71	100	Unbiased	19.62	19.655	0.0358
72	0	Control	20.685	19.829	-0.8561

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.685	20.685	20.685		19.829	19.829	19.829		-0.8561	-0.8561	-0.8561	
50	20.058	20.732	21.15	0.44483	19.401	20.262	21.105	0.64978	-1.6893	-0.47077	0.6833	1.026
100	19.62	20.492	21.059	0.51189	18.944	19.891	20.451	0.58206	-2.1148	-0.60063	0.2648	0.87123

Device Test: 95.13 DLH Dead Time Large 2MHz VIN_10V





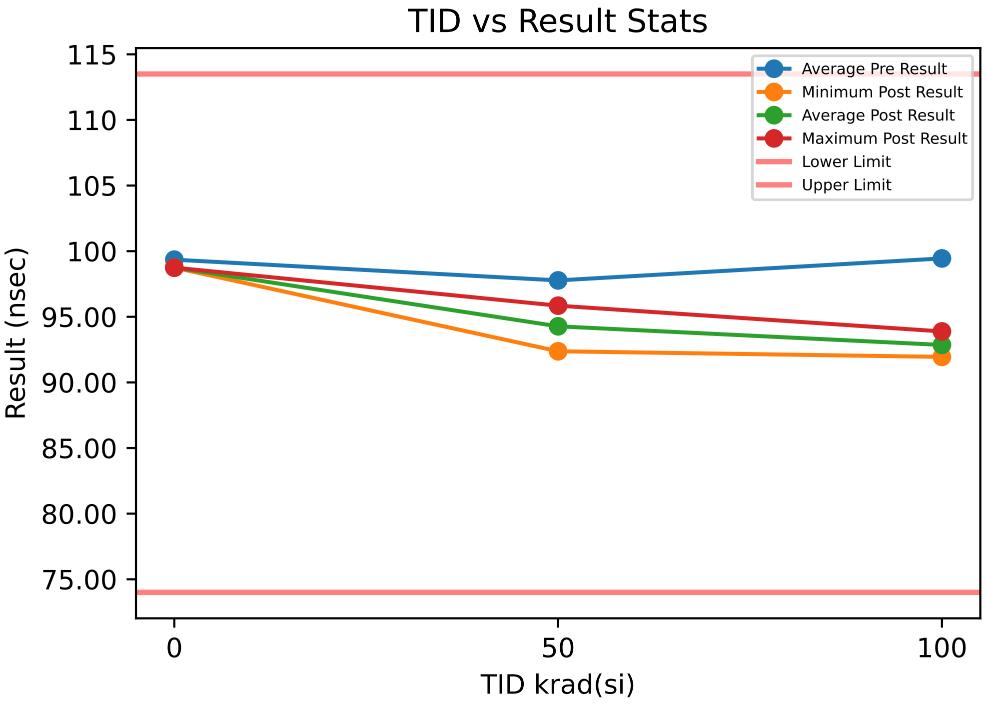
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

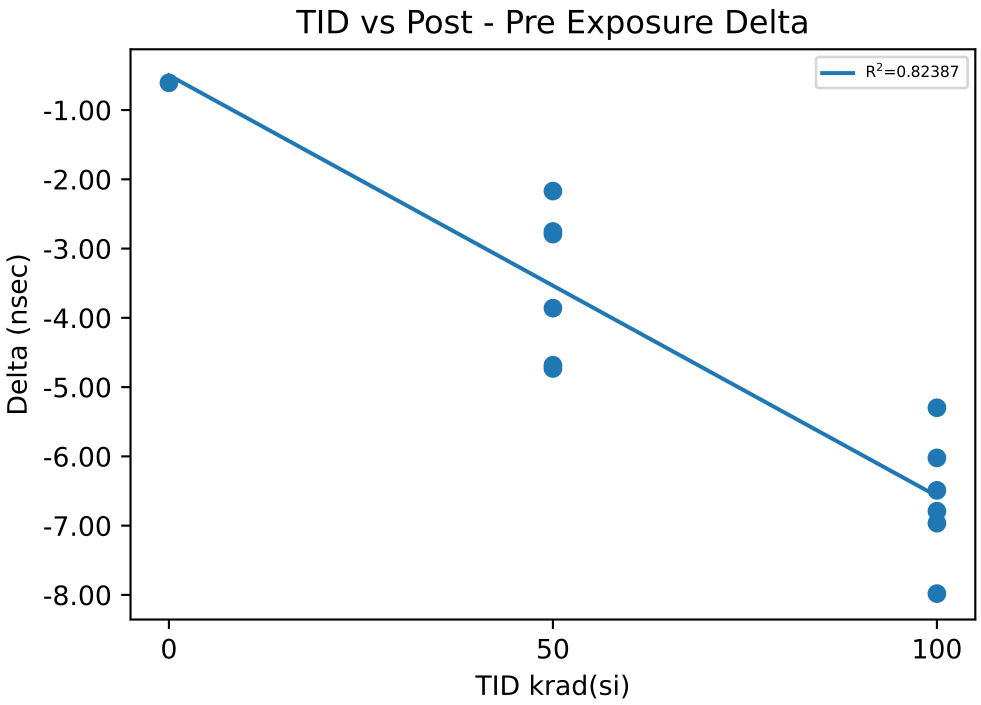
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	49.076	48.932	-0.1434
60	50	Biased	49.307	46.507	-2.8003
61	50	Biased	49.081	48.189	-0.8926
63	100	Biased	48.76	46.821	-1.9385
64	100	Biased	49.769	46.954	-2.8151
65	100	Biased	50.474	47.36	-3.1138
66	50	Unbiased	49.96	47.203	-2.757
67	50	Unbiased	49.175	48.49	-0.6853
68	50	Unbiased	49.844	47.794	-2.0498
69	100	Unbiased	50.428	47.475	-2.9538
70	100	Unbiased	50.466	46.333	-4.1337
71	100	Unbiased	49.543	47.267	-2.2758
72	0	Control	50.023	49.596	-0.4278

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.023	50.023	50.023		49.596	49.596	49.596		-0.4278	-0.4278	-0.4278	
50	49.076	49.407	49.96	0.394	46.507	47.852	48.932	0.88571	-2.8003	-1.5547	-0.1434	1.1339
100	48.76	49.907	50.474	0.68913	46.333	47.035	47.475	0.42392	-4.1337	-2.8718	-1.9385	0.75989

Device Test: 95.14 DLH Dead Time Max 2MHz VIN_10V





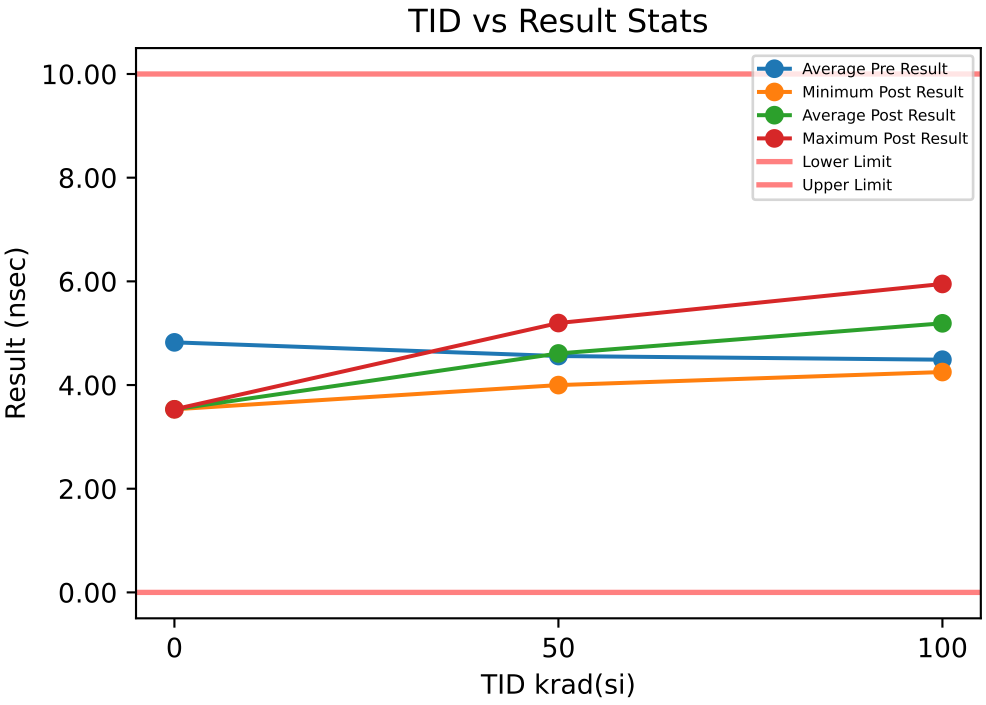
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

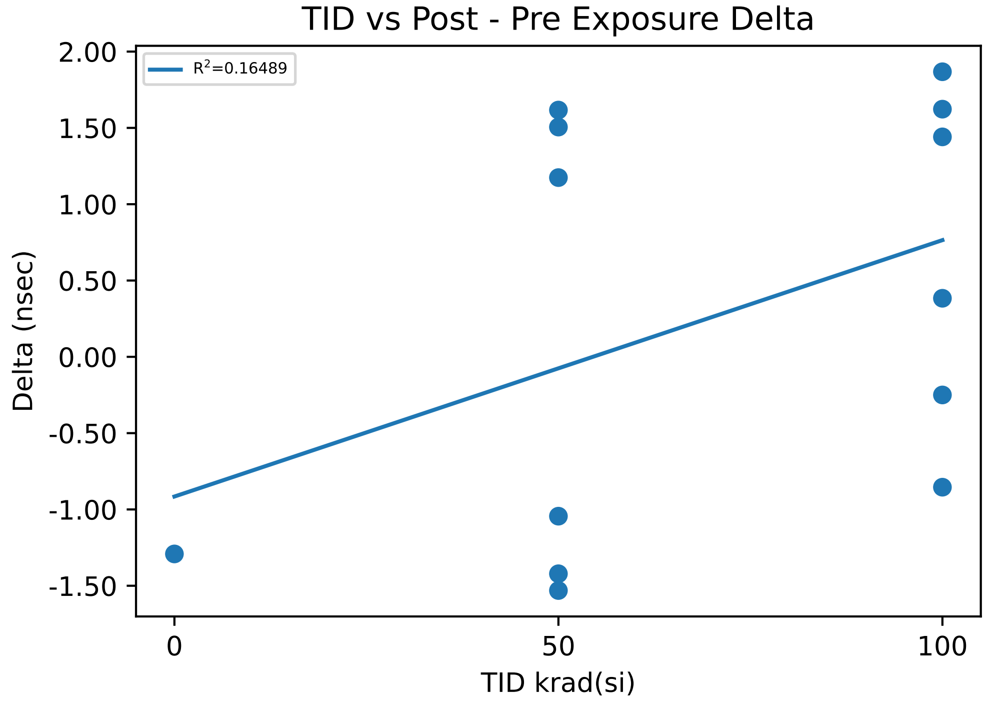
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	98.018	95.848	-2.17
60	50	Biased	97.105	92.373	-4.7314
61	50	Biased	97.26	94.469	-2.7912
63	100	Biased	97.268	91.97	-5.2984
64	100	Biased	98.435	91.944	-6.4906
65	100	Biased	100.55	93.758	-6.791
66	50	Unbiased	98.148	93.464	-4.6842
67	50	Unbiased	97.874	95.122	-2.7525
68	50	Unbiased	98.233	94.373	-3.8603
69	100	Unbiased	100.13	93.17	-6.9643
70	100	Unbiased	100.39	92.41	-7.981
71	100	Unbiased	99.907	93.885	-6.0218
72	0	Control	99.353	98.746	-0.6069

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.353	99.353	99.353		98.746	98.746	98.746		-0.6069	-0.6069	-0.6069	
50	97.105	97.773	98.233	0.47602	92.373	94.275	95.848	1.2258	-4.7314	-3.4983	-2.17	1.0843
100	97.268	99.447	100.55	1.3085	91.944	92.856	93.885	0.87014	-7.981	-6.5912	-5.2984	0.90734

Device Test: 95.19 DHL Dead Time Min 500kHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

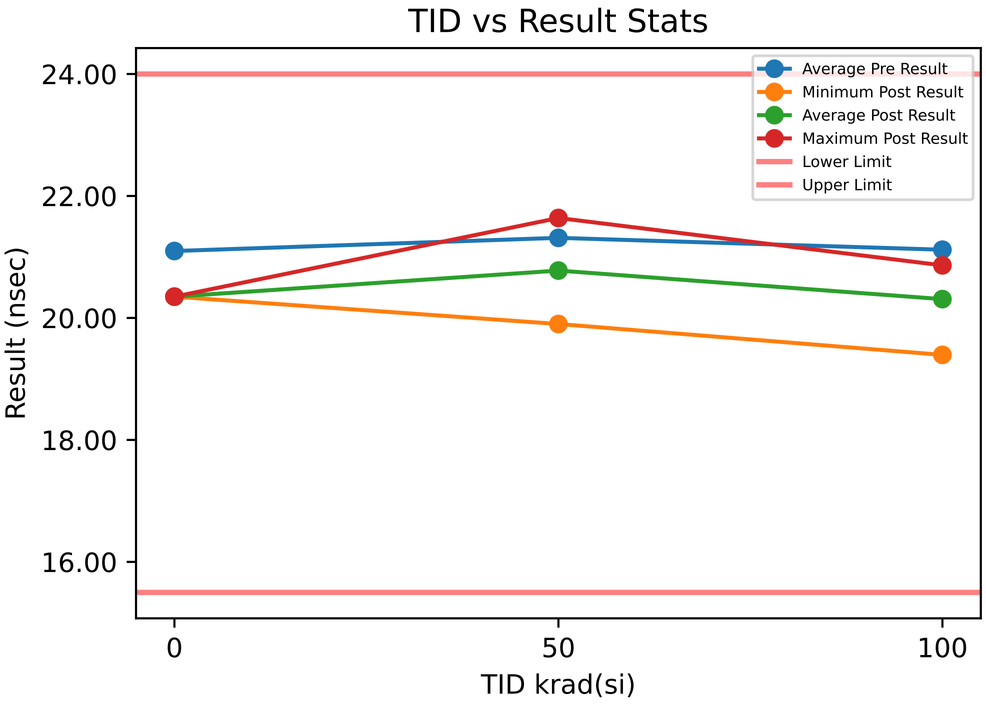
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

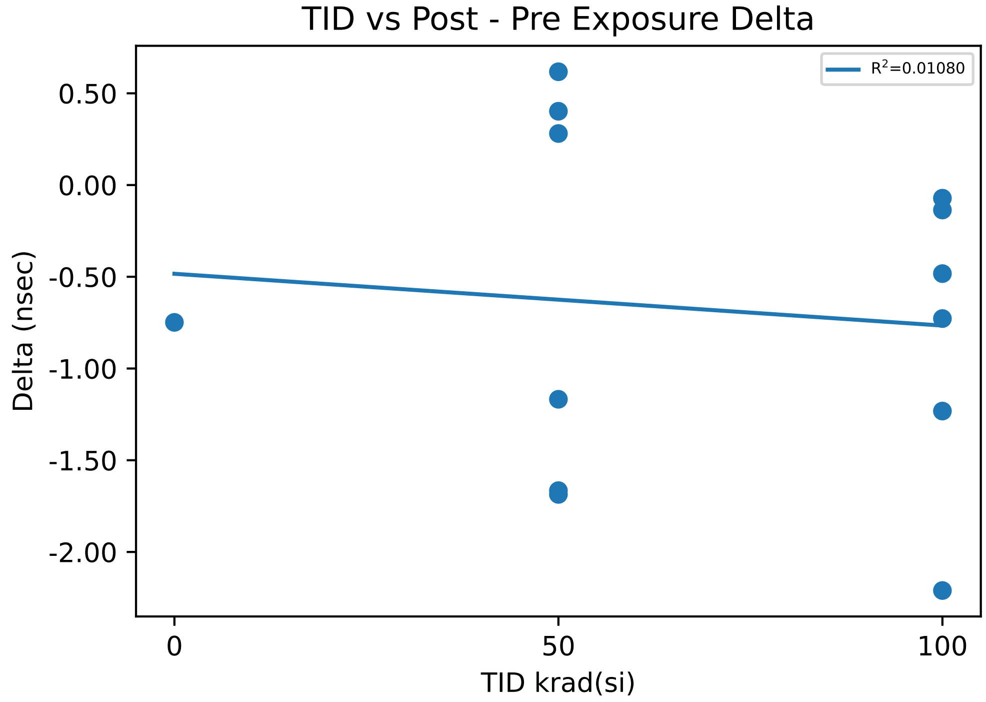
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.8366	5.011	1.1744
60	50	Biased	5.3389	4.2948	-1.0441
61	50	Biased	3.3253	4.9422	1.6169
63	100	Biased	3.5372	5.4051	1.8679
64	100	Biased	5.3429	5.0931	-0.2498
65	100	Biased	3.8671	4.2508	0.3837
66	50	Unbiased	5.6352	4.2139	-1.4213
67	50	Unbiased	3.6904	5.1959	1.5055
68	50	Unbiased	5.5302	3.999	-1.5312
69	100	Unbiased	4.5088	5.95	1.4412
70	100	Unbiased	5.7662	4.912	-0.8542
71	100	Unbiased	3.9102	5.533	1.6228
72	0	Control	4.8233	3.5318	-1.2915

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.8233	4.8233	4.8233		3.5318	3.5318	3.5318		-1.2915	-1.2915	-1.2915	
50	3.3253	4.5594	5.6352	1.0496	3.999	4.6095	5.1959	0.4988	-1.5312	0.050033	1.6169	1.5297
100	3.5372	4.4887	5.7662	0.89314	4.2508	5.1907	5.95	0.58486	-0.8542	0.70193	1.8679	1.112

Device Test: 95.2 DLH Dead Time Mid 500kHz VIN_10V





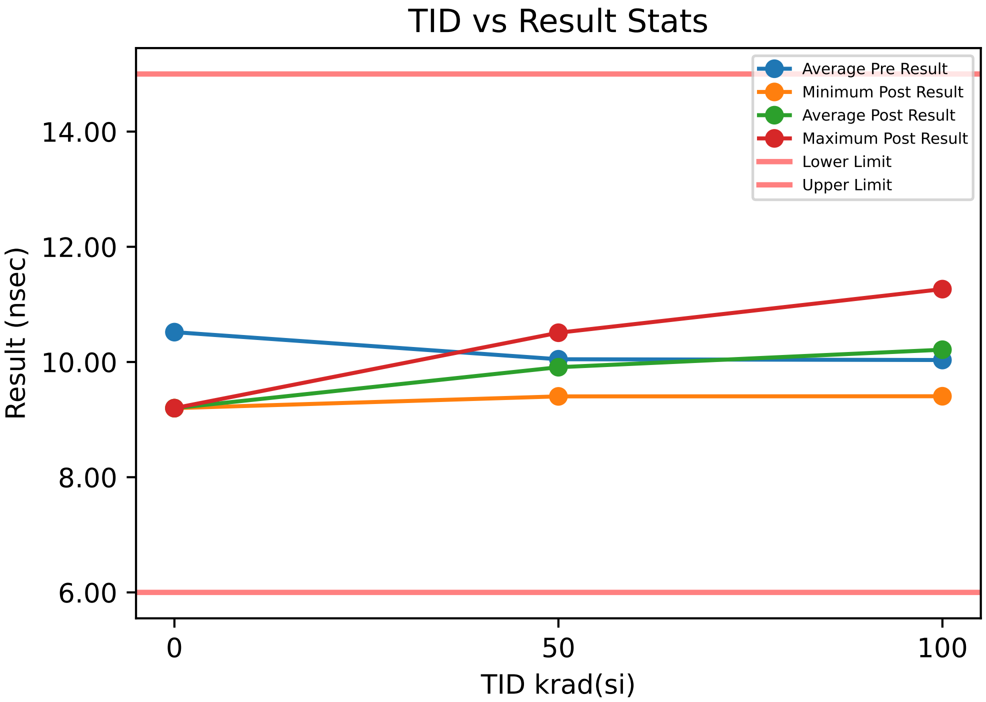
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

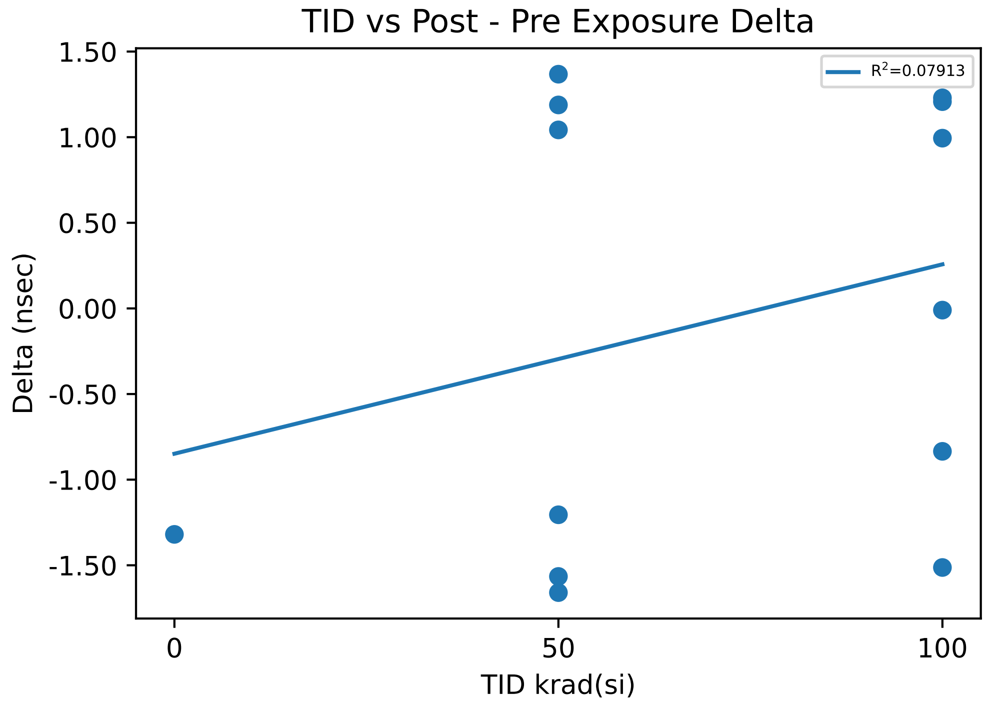
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	21.021	21.639	0.6175
60	50	Biased	21.566	19.901	-1.6657
61	50	Biased	21.116	21.397	0.2809
63	100	Biased	20.796	20.66	-0.1361
64	100	Biased	21.39	20.662	-0.7278
65	100	Biased	21.324	20.092	-1.232
66	50	Unbiased	21.72	20.034	-1.6862
67	50	Unbiased	20.658	21.06	0.4022
68	50	Unbiased	21.799	20.631	-1.1678
69	100	Unbiased	21.345	20.863	-0.4827
70	100	Unbiased	21.605	19.395	-2.2101
71	100	Unbiased	20.253	20.181	-0.0717
72	0	Control	21.098	20.349	-0.7486

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.098	21.098	21.098		20.349	20.349	20.349		-0.7486	-0.7486	-0.7486	
50	20.658	21.313	21.799	0.45135	19.901	20.777	21.639	0.71406	-1.6862	-0.53652	0.6175	1.0841
100	20.253	21.119	21.605	0.5013	19.395	20.309	20.863	0.53925	-2.2101	-0.81007	-0.0717	0.80641

Device Test: 95.20 DHL Dead Time Small 500kHz VIN_10V





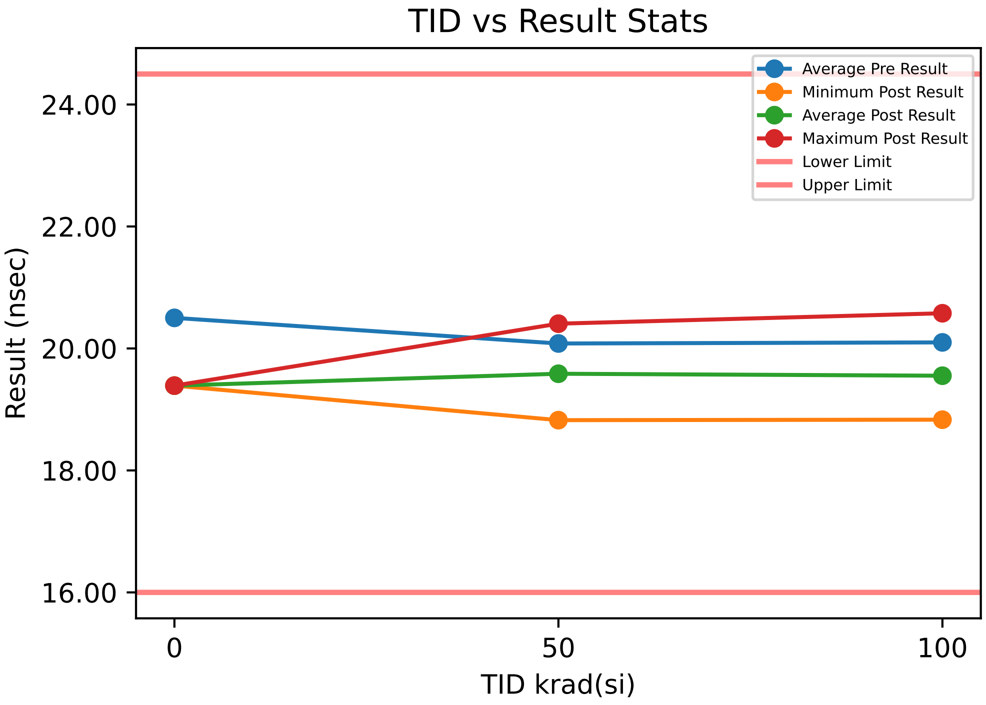
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

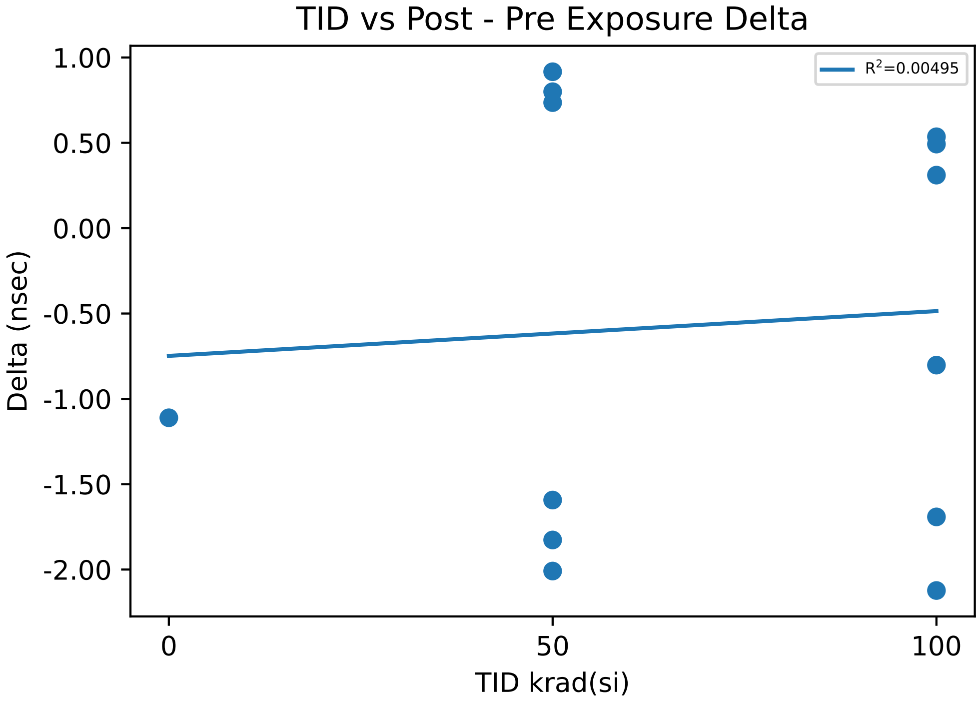
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	9.3448	10.387	1.0425
60	50	Biased	10.665	9.4602	-1.2051
61	50	Biased	8.9193	10.287	1.3678
63	100	Biased	9.2387	10.446	1.2075
64	100	Biased	10.735	9.9003	-0.8347
65	100	Biased	9.4153	9.4054	-0.0099
66	50	Unbiased	10.968	9.403	-1.5653
67	50	Unbiased	9.3197	10.508	1.1883
68	50	Unbiased	11.07	9.4105	-1.6596
69	100	Unbiased	10.036	11.265	1.2295
70	100	Unbiased	11.308	9.795	-1.513
71	100	Unbiased	9.4733	10.468	0.9943
72	0	Control	10.518	9.1989	-1.3196

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.518	10.518	10.518		9.1989	9.1989	9.1989		-1.3196	-1.3196	-1.3196	
50	8.9193	10.048	11.07	0.9562	9.403	9.9093	10.508	0.536	-1.6596	-0.13857	1.3678	1.4772
100	9.2387	10.034	11.308	0.82996	9.4054	10.213	11.265	0.6559	-1.513	0.17895	1.2295	1.1621

Device Test: 95.21 DHL Dead Time Mid 500kHz VIN_10V





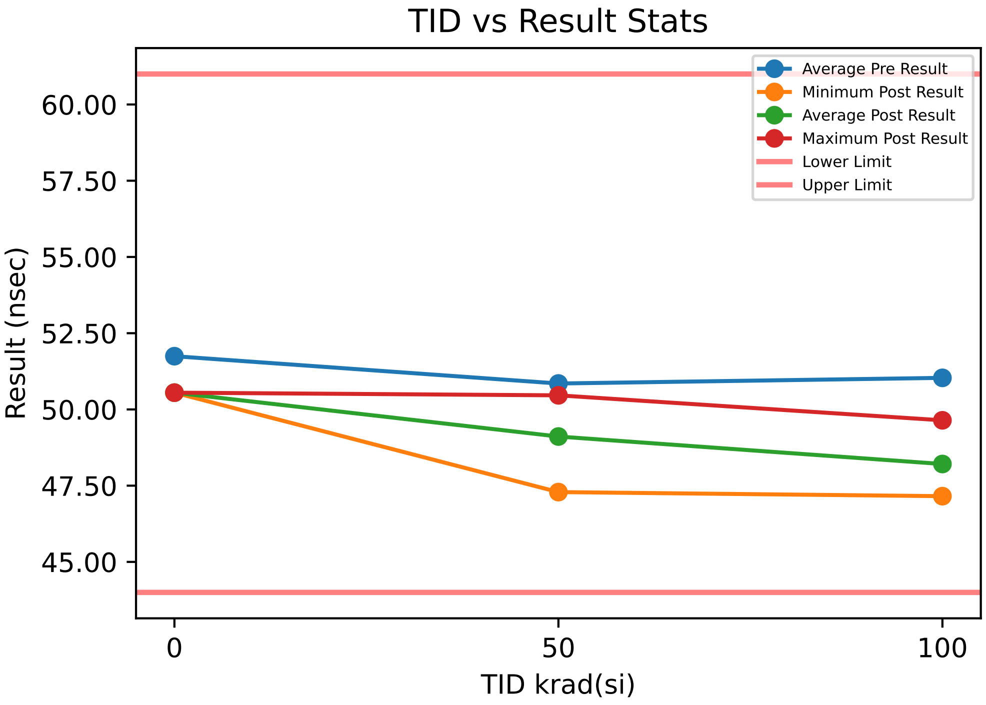
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

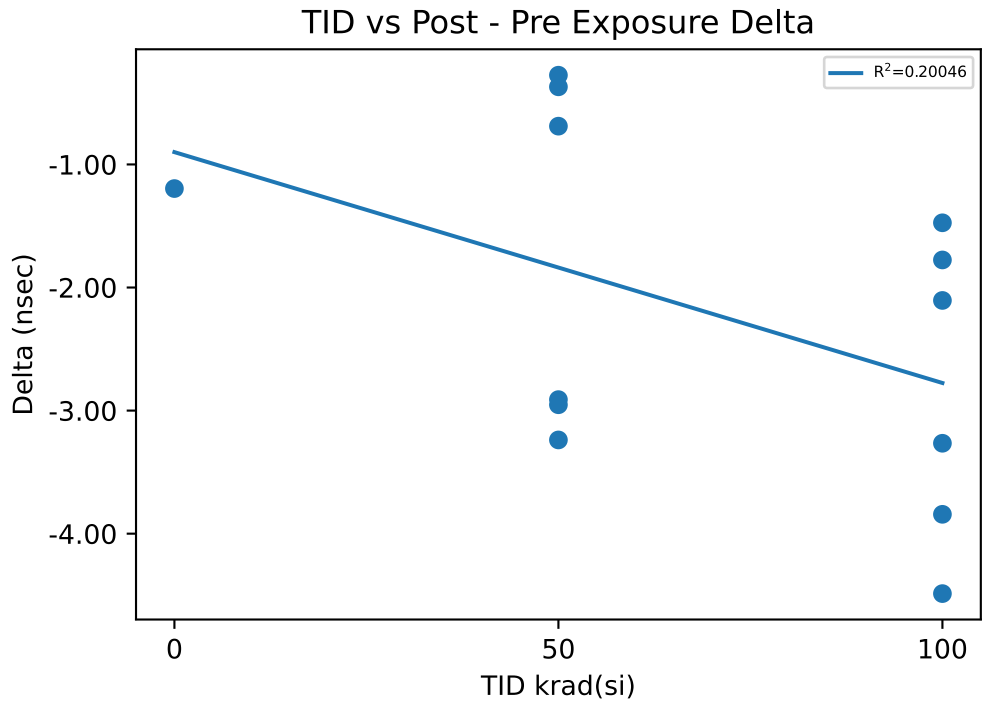
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	19.221	19.957	0.7356
60	50	Biased	20.653	19.06	-1.5929
61	50	Biased	19.259	20.175	0.9164
63	100	Biased	19.418	19.953	0.5355
64	100	Biased	20.721	19.029	-1.6916
65	100	Biased	19.634	18.832	-0.8024
66	50	Unbiased	20.651	18.824	-1.8268
67	50	Unbiased	19.607	20.406	0.7994
68	50	Unbiased	21.097	19.088	-2.0088
69	100	Unbiased	20.266	20.577	0.3107
70	100	Unbiased	21.168	19.045	-2.1229
71	100	Unbiased	19.388	19.881	0.4926
72	0	Control	20.501	19.39	-1.1109

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.501	20.501	20.501		19.39	19.39	19.39		-1.1109	-1.1109	-1.1109	
50	19.221	20.081	21.097	0.81553	18.824	19.585	20.406	0.67253	-2.0088	-0.49618	0.9164	1.4459
100	19.388	20.099	21.168	0.74065	18.832	19.553	20.577	0.68822	-2.1229	-0.54635	0.5355	1.1702

Device Test: 95.22 DHL Dead Time Large 500kHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

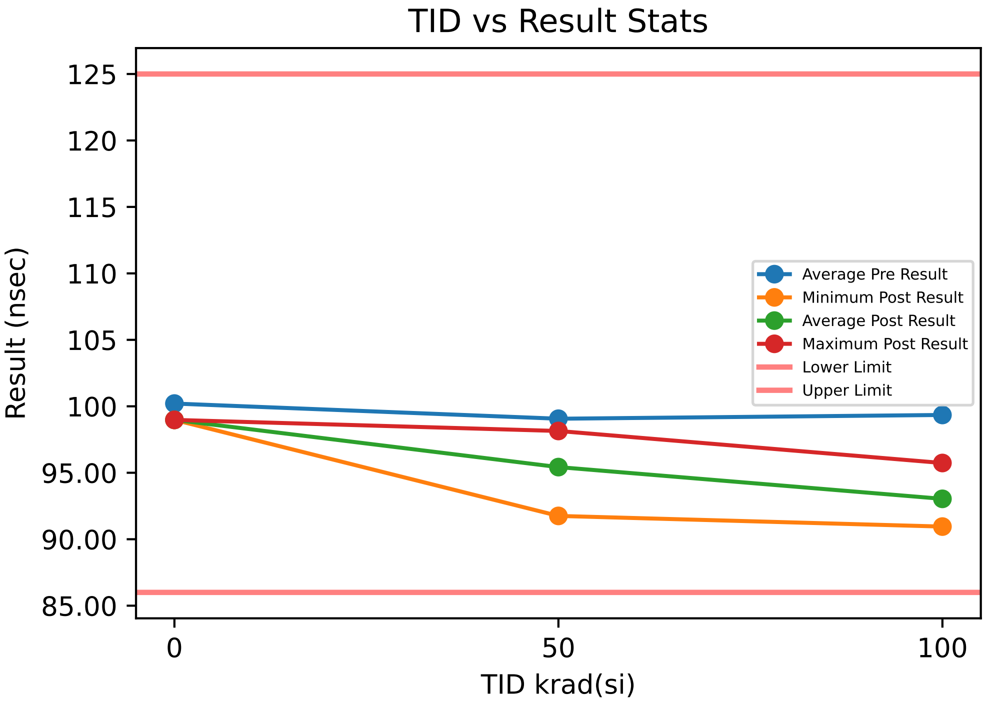
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	50.154	49.465	-0.689
60	50	Biased	51.358	48.447	-2.9108
61	50	Biased	50.773	50.404	-0.3693
63	100	Biased	50.709	48.934	-1.776
64	100	Biased	51	47.158	-3.8427
65	100	Biased	51.027	47.761	-3.2654
66	50	Unbiased	50.242	47.289	-2.9525
67	50	Unbiased	50.737	50.462	-0.2749
68	50	Unbiased	51.839	48.601	-3.2384
69	100	Unbiased	51.748	49.643	-2.105
70	100	Unbiased	51.642	47.156	-4.4869
71	100	Unbiased	50.086	48.611	-1.4741
72	0	Control	51.746	50.55	-1.1959

Test Statistics (nsec)

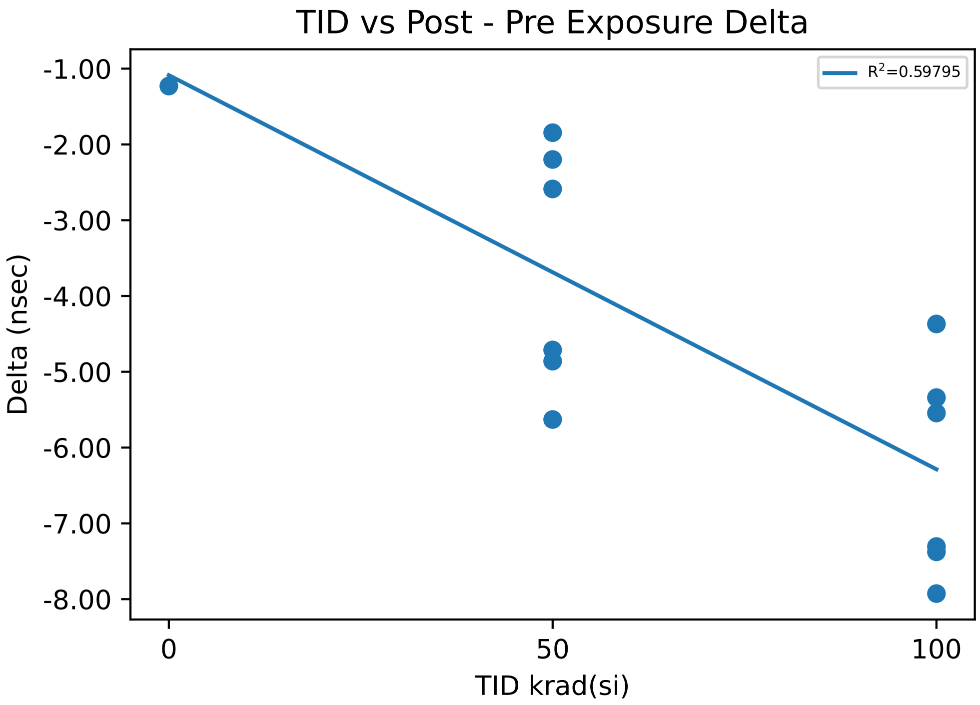
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	51.746	51.746	51.746		50.55	50.55	50.55		-1.1959	-1.1959	-1.1959	
50	50.154	50.851	51.839	0.6495	47.289	49.111	50.462	1.2362	-3.2384	-1.7391	-0.2749	1.4294
100	50.086	51.036	51.748	0.61426	47.156	48.21	49.643	1.0158	-4.4869	-2.825	-1.4741	1.2195

Device Test: 95.23 DHL Dead Time Max 500kHz VIN_10V



Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

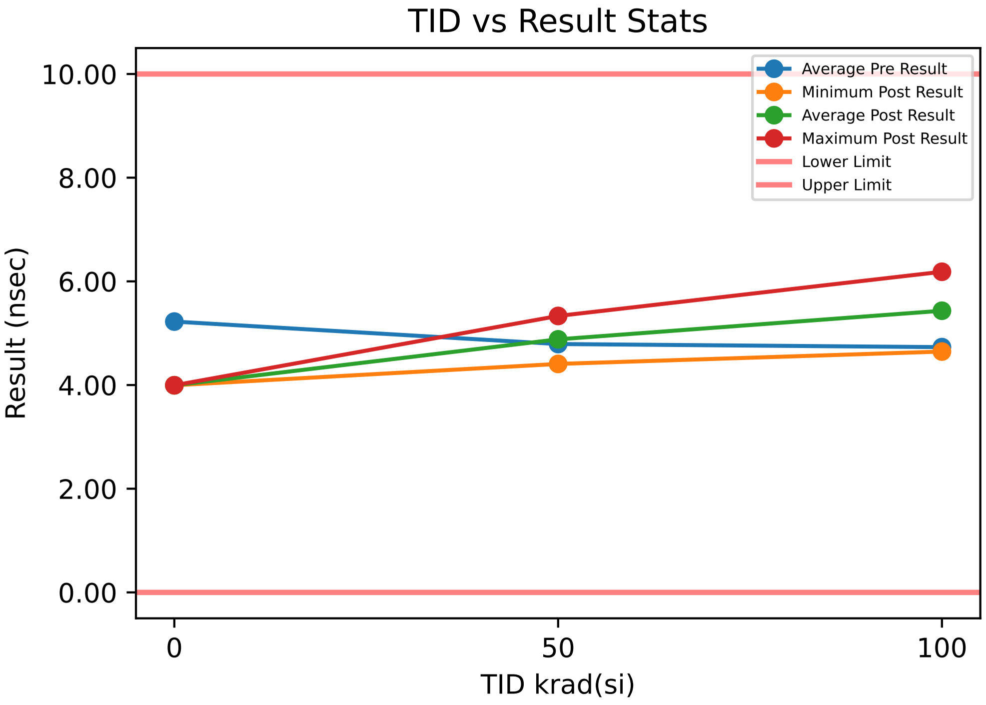
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	98.087	95.499	-2.5876
60	50	Biased	99.682	94.822	-4.8596
61	50	Biased	100.34	98.144	-2.1985
63	100	Biased	100.03	94.484	-5.5438
64	100	Biased	98.439	91.063	-7.376
65	100	Biased	100.07	92.763	-7.3056
66	50	Unbiased	96.466	91.754	-4.7121
67	50	Unbiased	99.485	97.64	-1.8451
68	50	Unbiased	100.33	94.702	-5.6295
69	100	Unbiased	101.08	95.735	-5.3403
70	100	Unbiased	98.879	90.952	-7.9267
71	100	Unbiased	97.602	93.233	-4.3691
72	0	Control	100.21	98.978	-1.2296

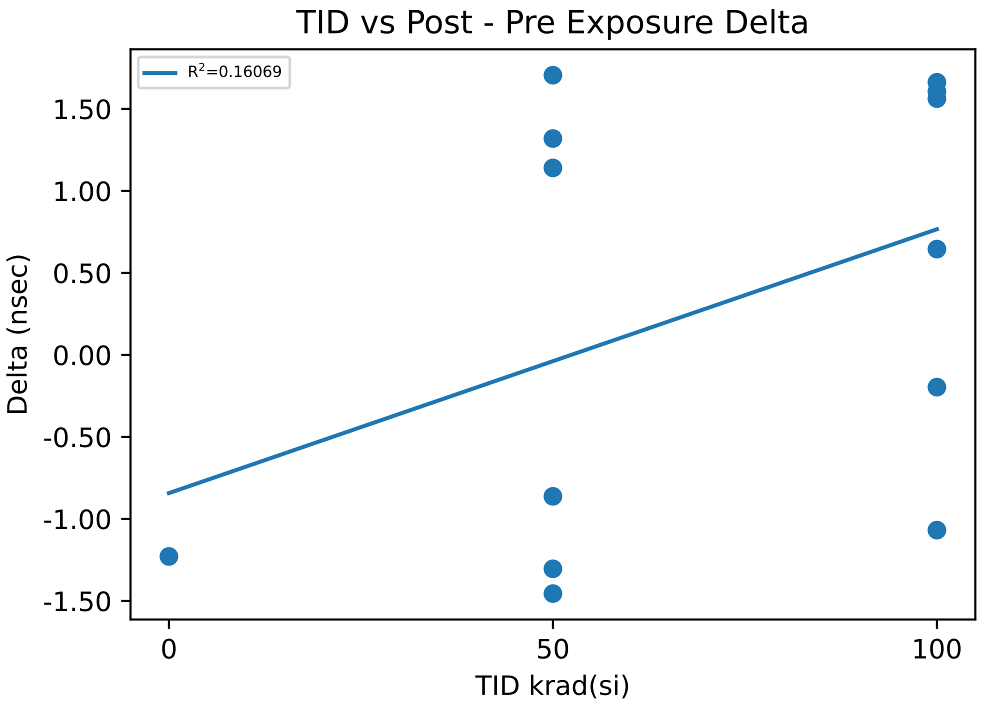


Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100.21	100.21	100.21		98.978	98.978	98.978		-1.2296	-1.2296	-1.2296	
50	96.466	99.066	100.34	1.5169	91.754	95.427	98.144	2.3095	-5.6295	-3.6387	-1.8451	1.6126
100	97.602	99.349	101.08	1.2696	90.952	93.038	95.735	1.8832	-7.9267	-6.3103	-4.3691	1.4167

Device Test: 95.24 DHL Dead Time Min 1MHz VIN_10V





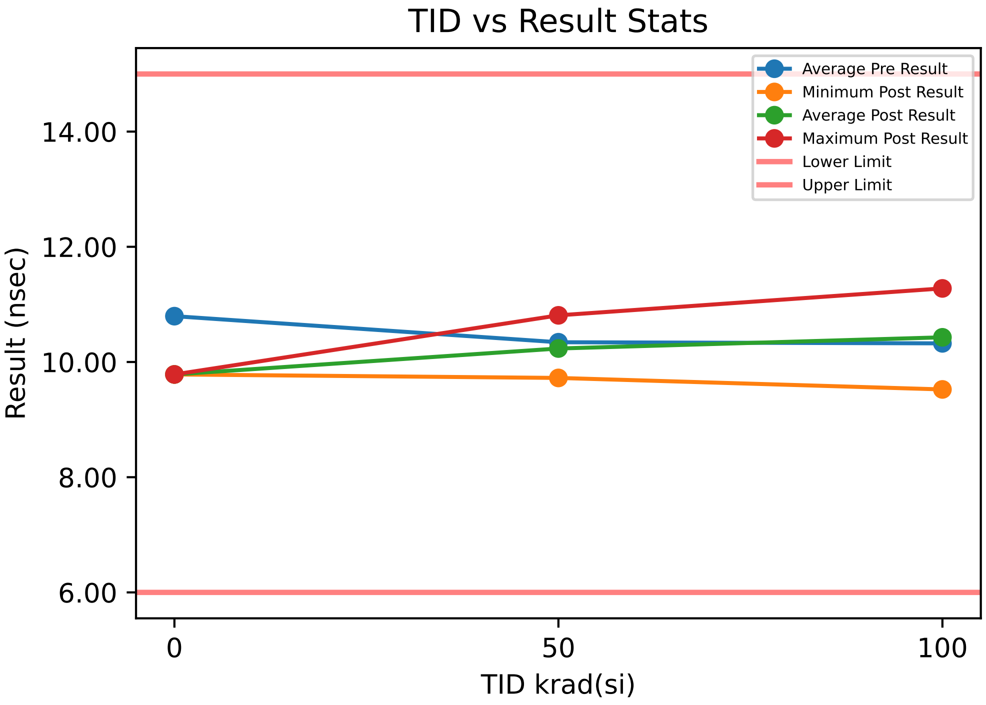
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

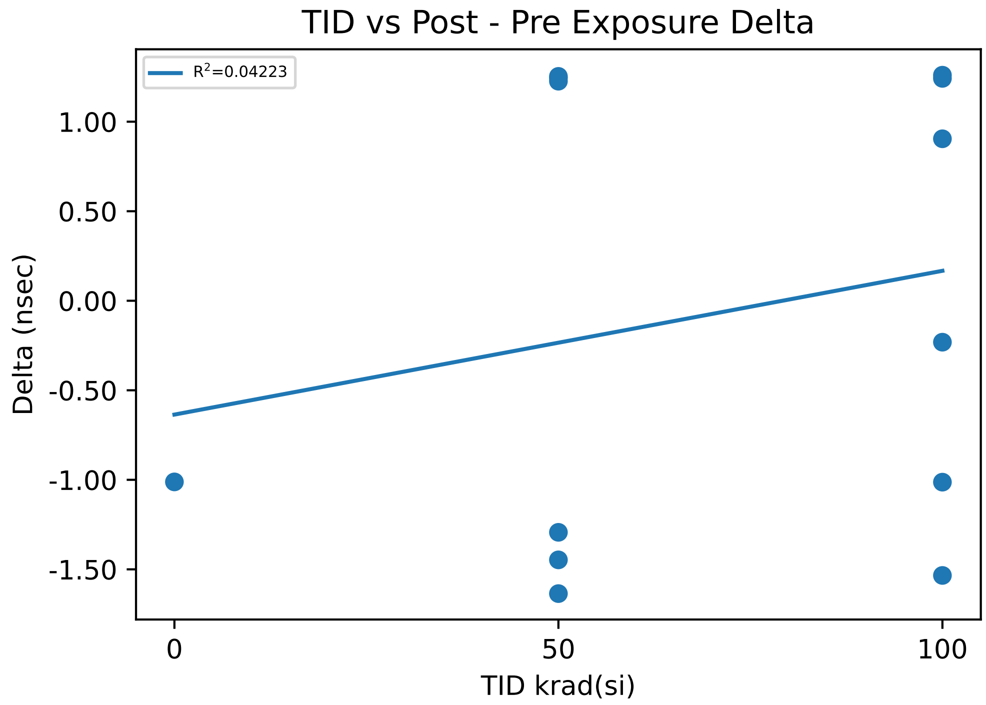
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.1022	5.2424	1.1402
60	50	Biased	5.4495	4.5872	-0.8623
61	50	Biased	3.5851	5.2906	1.7055
63	100	Biased	3.983	5.6453	1.6623
64	100	Biased	5.5433	5.3469	-0.1964
65	100	Biased	4.0007	4.6459	0.6452
66	50	Unbiased	5.8626	4.4073	-1.4553
67	50	Unbiased	4.0134	5.3327	1.3193
68	50	Unbiased	5.7331	4.4289	-1.3042
69	100	Unbiased	4.5787	6.1849	1.6062
70	100	Unbiased	6.0785	5.0101	-1.0684
71	100	Unbiased	4.2024	5.7651	1.5627
72	0	Control	5.2242	3.9954	-1.2288

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.2242	5.2242	5.2242		3.9954	3.9954	3.9954		-1.2288	-1.2288	-1.2288	
50	3.5851	4.791	5.8626	1.0003	4.4073	4.8815	5.3327	0.45111	-1.4553	0.090533	1.7055	1.4466
100	3.983	4.7311	6.0785	0.87989	4.6459	5.433	6.1849	0.55254	-1.0684	0.70193	1.6623	1.1336

Device Test: 95.25 DHL Dead Time Small 1MHz VIN_10V





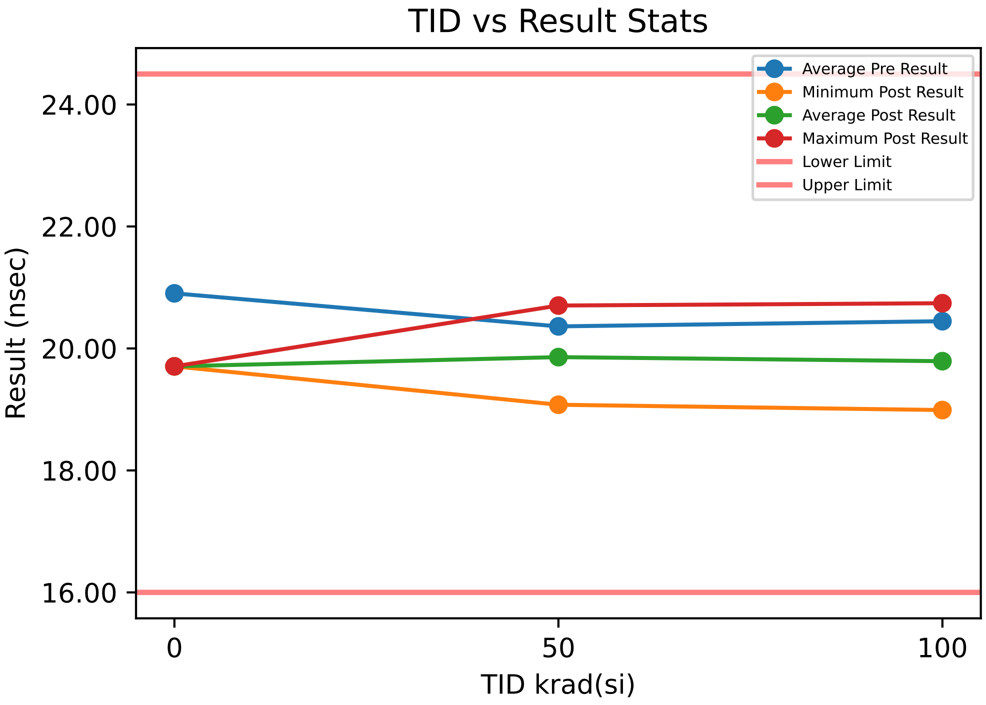
Test Results (Lower Limit = 6.0,
Upper Limit = 15.0 (nsec))

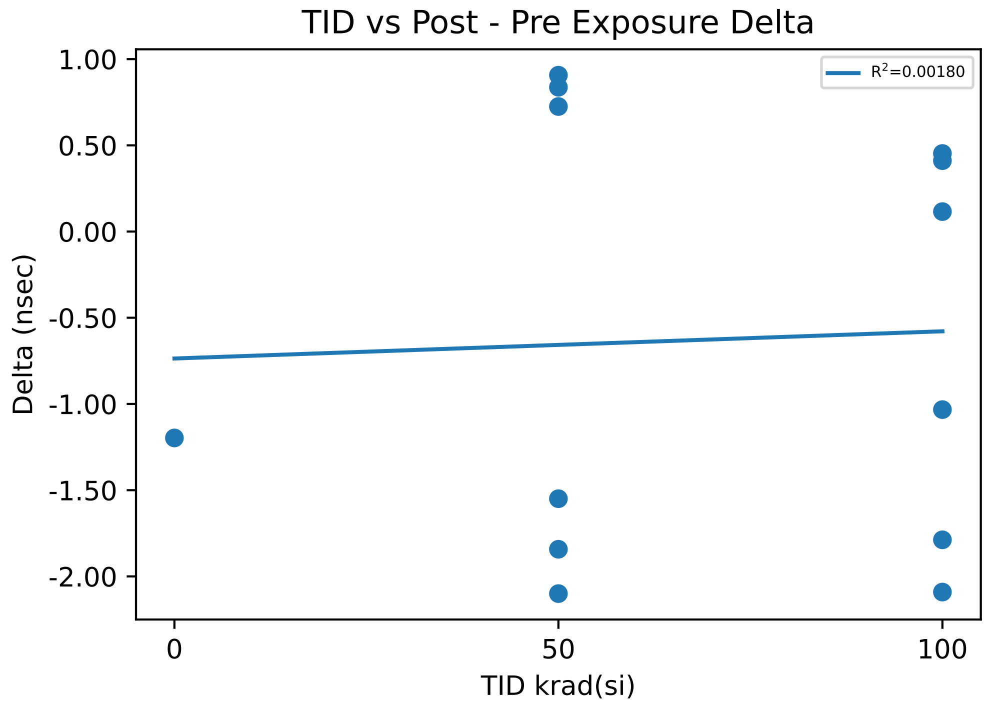
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	9.5839	10.81	1.2262
60	50	Biased	11.08	9.7864	-1.2933
61	50	Biased	9.3181	10.561	1.243
63	100	Biased	9.4807	10.74	1.2597
64	100	Biased	11.039	10.025	-1.0131
65	100	Biased	9.7552	9.5238	-0.2314
66	50	Unbiased	11.171	9.7234	-1.4471
67	50	Unbiased	9.5312	10.784	1.2531
68	50	Unbiased	11.375	9.7398	-1.6355
69	100	Unbiased	10.373	11.278	0.9046
70	100	Unbiased	11.565	10.03	-1.5341
71	100	Unbiased	9.7307	10.973	1.2419
72	0	Control	10.796	9.7839	-1.0117

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.796	10.796	10.796		9.7839	9.7839	9.7839		-1.0117	-1.0117	-1.0117	
50	9.3181	10.343	11.375	0.95695	9.7234	10.234	10.81	0.53796	-1.6355	-0.10893	1.2531	1.4825
100	9.4807	10.324	11.565	0.82929	9.5238	10.428	11.278	0.67137	-1.5341	0.1046	1.2597	1.2096

Device Test: 95.26 DHL Dead Time Mid 1MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

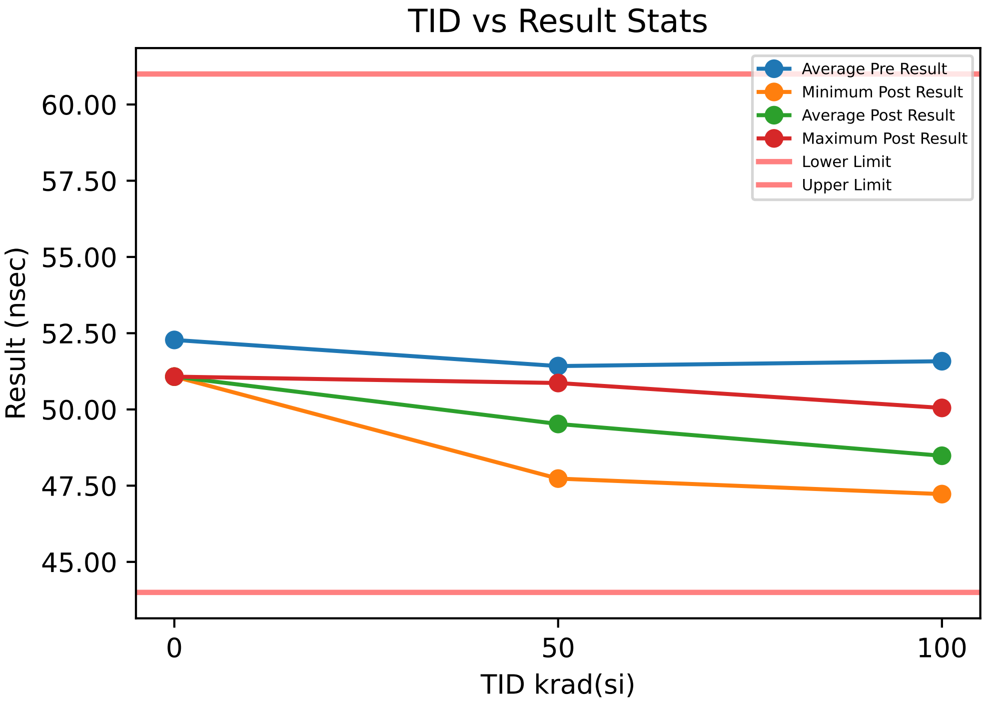
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

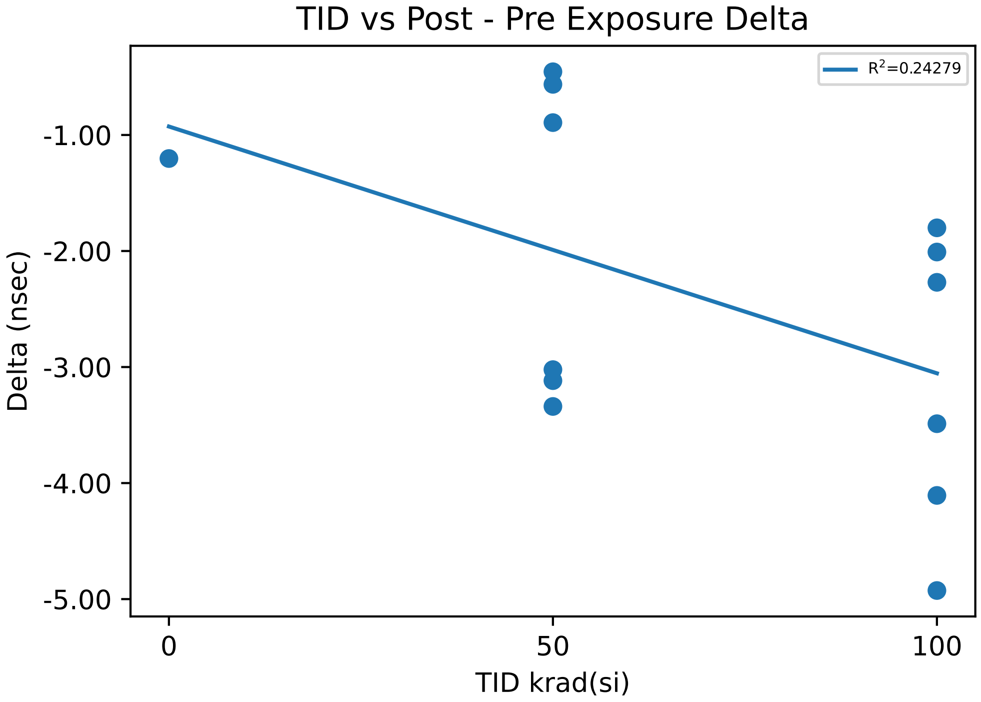
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	19.542	20.267	0.725
60	50	Biased	20.962	19.412	-1.5495
61	50	Biased	19.566	20.403	0.8369
63	100	Biased	19.711	20.164	0.4527
64	100	Biased	20.982	19.194	-1.7879
65	100	Biased	20.023	18.99	-1.0327
66	50	Unbiased	20.919	19.077	-1.8426
67	50	Unbiased	19.797	20.704	0.9067
68	50	Unbiased	21.384	19.284	-2.0998
69	100	Unbiased	20.626	20.741	0.1156
70	100	Unbiased	21.531	19.441	-2.0909
71	100	Unbiased	19.807	20.218	0.4109
72	0	Control	20.903	19.706	-1.1971

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.903	20.903	20.903		19.706	19.706	19.706		-1.1971	-1.1971	-1.1971	
50	19.542	20.362	21.384	0.81747	19.077	19.858	20.704	0.68075	-2.0998	-0.50388	0.9067	1.4649
100	19.711	20.447	21.531	0.7246	18.99	19.791	20.741	0.68496	-2.0909	-0.65538	0.4527	1.1353

Device Test: 95.27 DHL Dead Time Large 1MHz VIN_10V





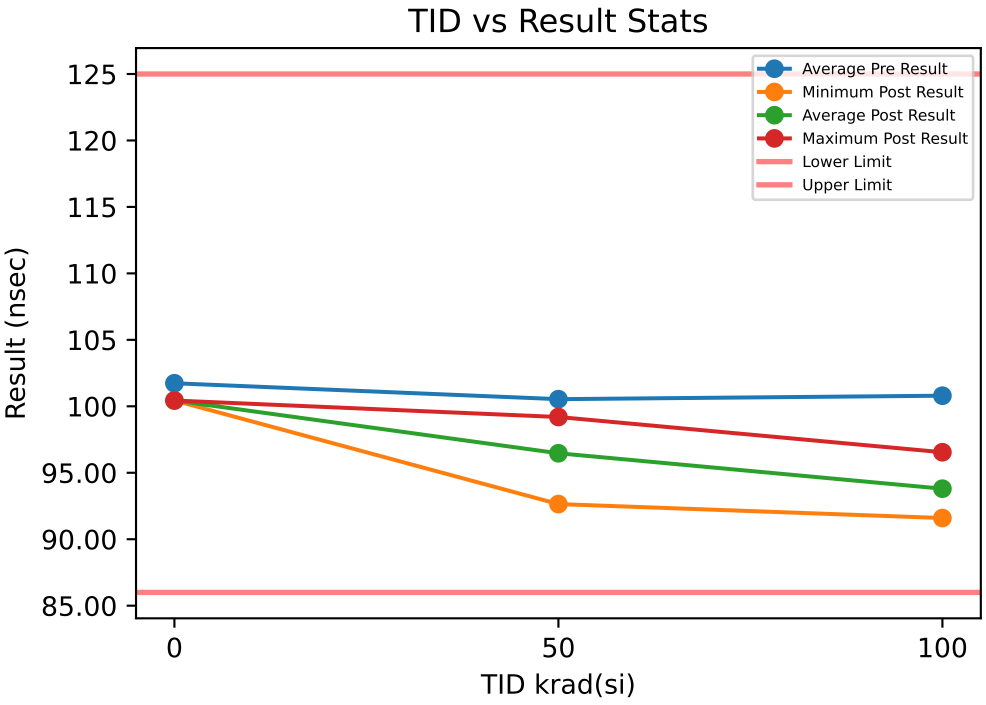
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

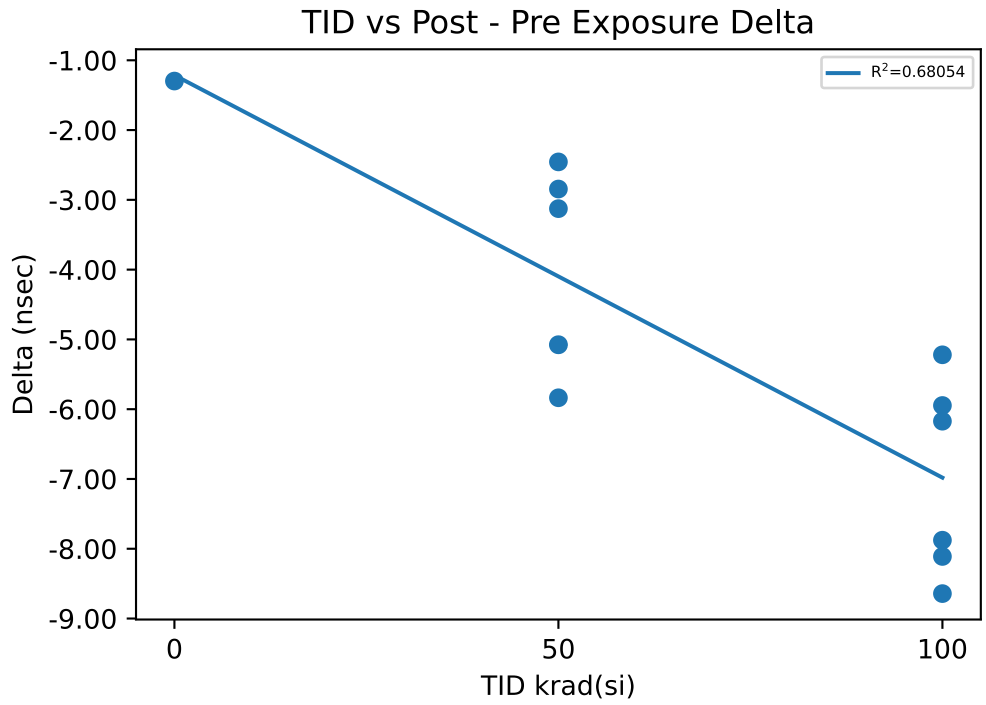
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	50.7	49.806	-0.8934
60	50	Biased	51.858	48.741	-3.1172
61	50	Biased	51.322	50.867	-0.4551
63	100	Biased	51.181	49.172	-2.0087
64	100	Biased	51.628	47.522	-4.1064
65	100	Biased	51.677	48.189	-3.4884
66	50	Unbiased	50.754	47.732	-3.0223
67	50	Unbiased	51.378	50.814	-0.5637
68	50	Unbiased	52.52	49.181	-3.3397
69	100	Unbiased	52.32	50.05	-2.2699
70	100	Unbiased	52.149	47.223	-4.926
71	100	Unbiased	50.53	48.73	-1.8003
72	0	Control	52.279	51.076	-1.2029

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.279	52.279	52.279		51.076	51.076	51.076		-1.2029	-1.2029	-1.2029	
50	50.7	51.422	52.52	0.68936	47.732	49.523	50.867	1.2238	-3.3397	-1.8986	-0.4551	1.3929
100	50.53	51.581	52.32	0.65497	47.223	48.481	50.05	1.0572	-4.926	-3.1	-1.8003	1.2702

Device Test: 95.28 DHL Dead Time Max 1MHz VIN_10V





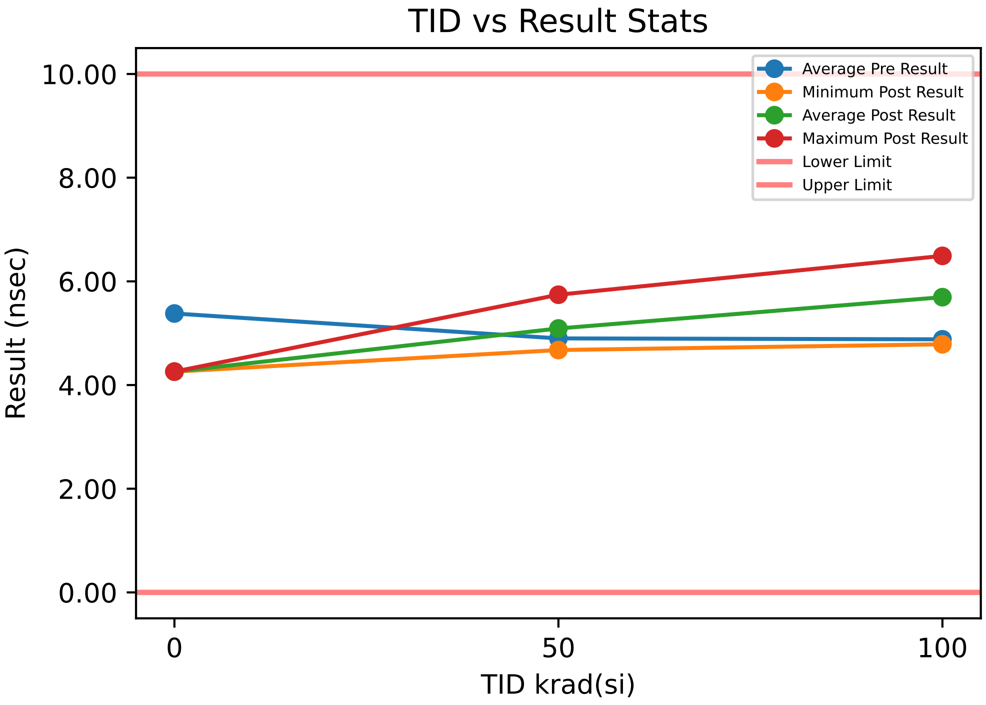
Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

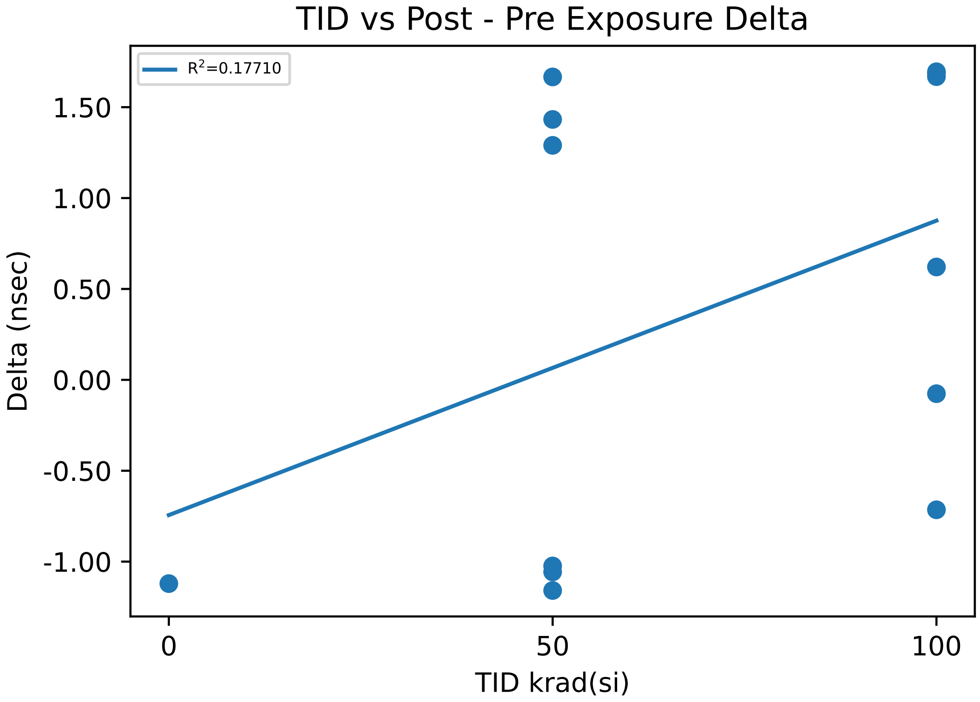
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	99.616	96.49	-3.1261
60	50	Biased	101.04	95.968	-5.0759
61	50	Biased	102.04	99.195	-2.8448
63	100	Biased	101.51	95.339	-6.1722
64	100	Biased	99.9	91.789	-8.1105
65	100	Biased	101.51	93.631	-7.8774
66	50	Unbiased	97.722	92.645	-5.0772
67	50	Unbiased	101.03	98.577	-2.4563
68	50	Unbiased	101.77	95.935	-5.8364
69	100	Unbiased	102.49	96.544	-5.9469
70	100	Unbiased	100.24	91.594	-8.6427
71	100	Unbiased	99.137	93.916	-5.2205
72	0	Control	101.73	100.44	-1.2976

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	101.73	101.73	101.73		100.44	100.44	100.44		-1.2976	-1.2976	-1.2976	
50	97.722	100.54	102.04	1.6161	92.645	96.468	99.195	2.3254	-5.8364	-4.0694	-2.4563	1.4243
100	99.137	100.8	102.49	1.2458	91.594	93.802	96.544	1.9416	-8.6427	-6.995	-5.2205	1.3901

Device Test: 95.29 DHL Dead Time Min 2MHz VIN_10V





Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

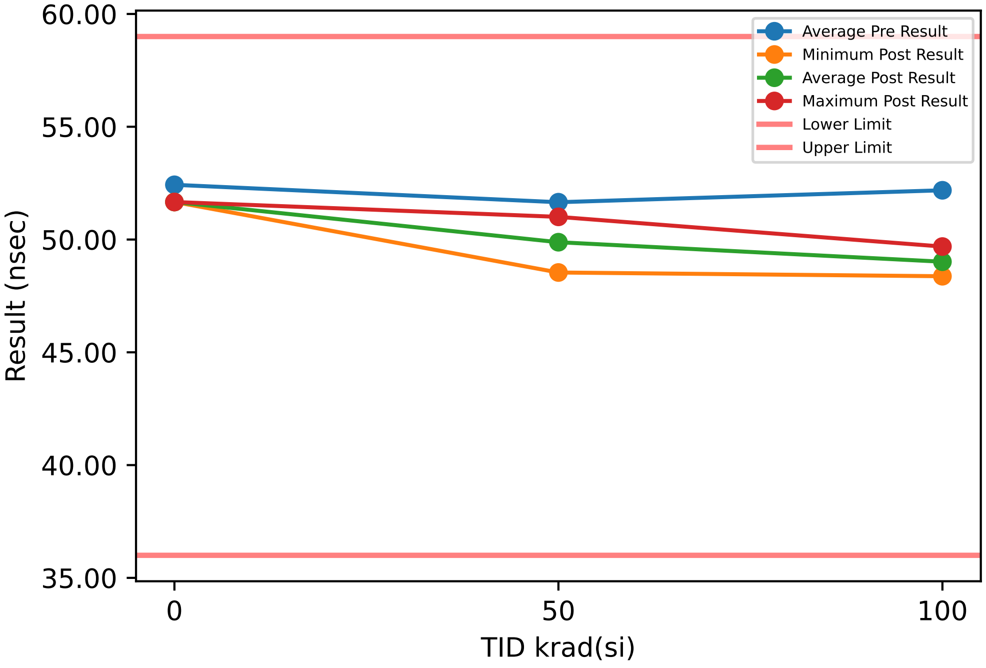
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.0489	5.3389	1.29
60	50	Biased	5.6991	4.6751	-1.024
61	50	Biased	3.8512	5.2837	1.4325
63	100	Biased	4.1696	5.8545	1.6849
64	100	Biased	5.6328	5.5566	-0.0762
65	100	Biased	4.1651	4.786	0.6209
66	50	Unbiased	5.8639	4.7049	-1.159
67	50	Unbiased	4.0757	5.7421	1.6664
68	50	Unbiased	5.8592	4.8024	-1.0568
69	100	Unbiased	4.8237	6.4917	1.668
70	100	Unbiased	6.1715	5.4566	-0.7149
71	100	Unbiased	4.3287	6.0236	1.6949
72	0	Control	5.38	4.259	-1.121

Test Statistics (nsec)

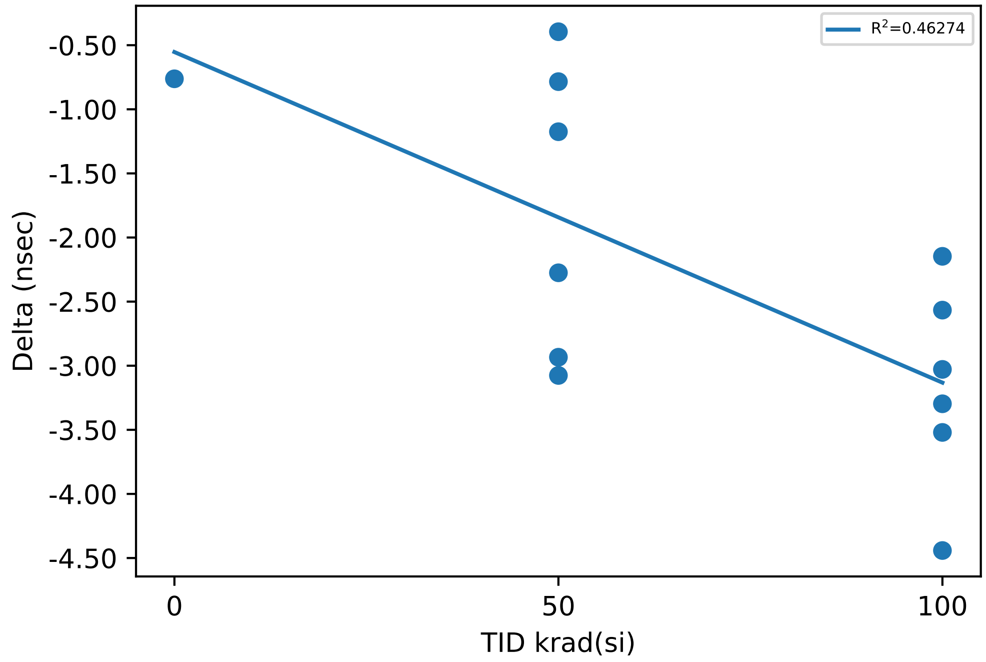
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.38	5.38	5.38		4.259	4.259	4.259		-1.121	-1.121	-1.121	
50	3.8512	4.8997	5.8639	0.99915	4.6751	5.0912	5.7421	0.43078	-1.159	0.19152	1.6664	1.3987
100	4.1651	4.8819	6.1715	0.84351	4.786	5.6948	6.4917	0.578	-0.7149	0.81293	1.6949	1.0422

Device Test: 95.3 DLH Dead Time Large 500kHz VIN_10V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



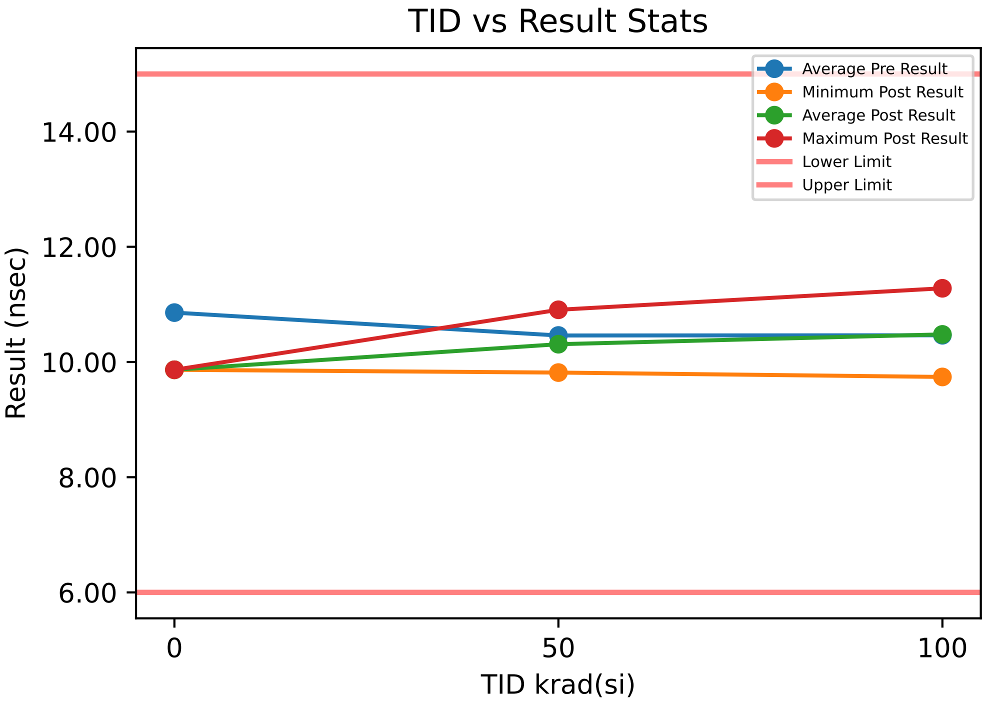
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

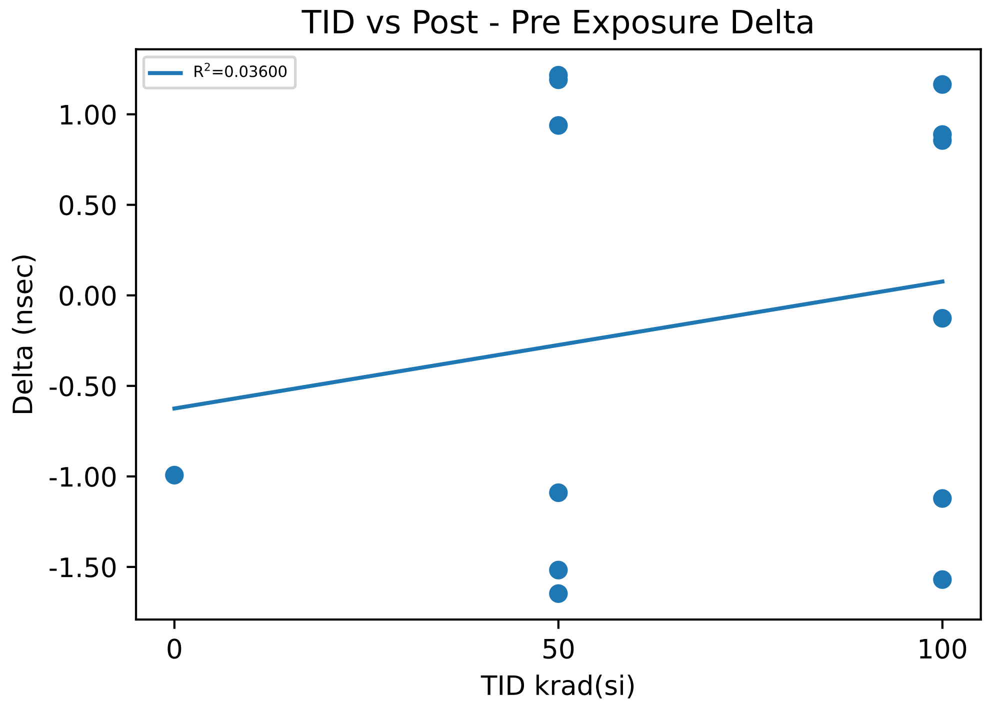
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	51.4	51.005	-0.395
60	50	Biased	51.614	48.538	-3.0759
61	50	Biased	51.363	50.188	-1.1749
63	100	Biased	50.951	48.804	-2.1468
64	100	Biased	51.934	48.637	-3.2969
65	100	Biased	52.827	49.306	-3.5203
66	50	Unbiased	52.136	49.202	-2.9338
67	50	Unbiased	51.303	50.519	-0.7843
68	50	Unbiased	52.109	49.834	-2.2752
69	100	Unbiased	52.717	49.688	-3.0288
70	100	Unbiased	52.814	48.373	-4.4414
71	100	Unbiased	51.856	49.289	-2.5664
72	0	Control	52.426	51.664	-0.7622

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.426	52.426	52.426		51.664	51.664	51.664		-0.7622	-0.7622	-0.7622	
50	51.303	51.654	52.136	0.37756	48.538	49.881	51.005	0.89786	-3.0759	-1.7732	-0.395	1.1429
100	50.951	52.183	52.827	0.74636	48.373	49.016	49.688	0.49262	-4.4414	-3.1668	-2.1468	0.7983

Device Test: 95.30 DHL Dead Time Small 2MHz VIN_10V





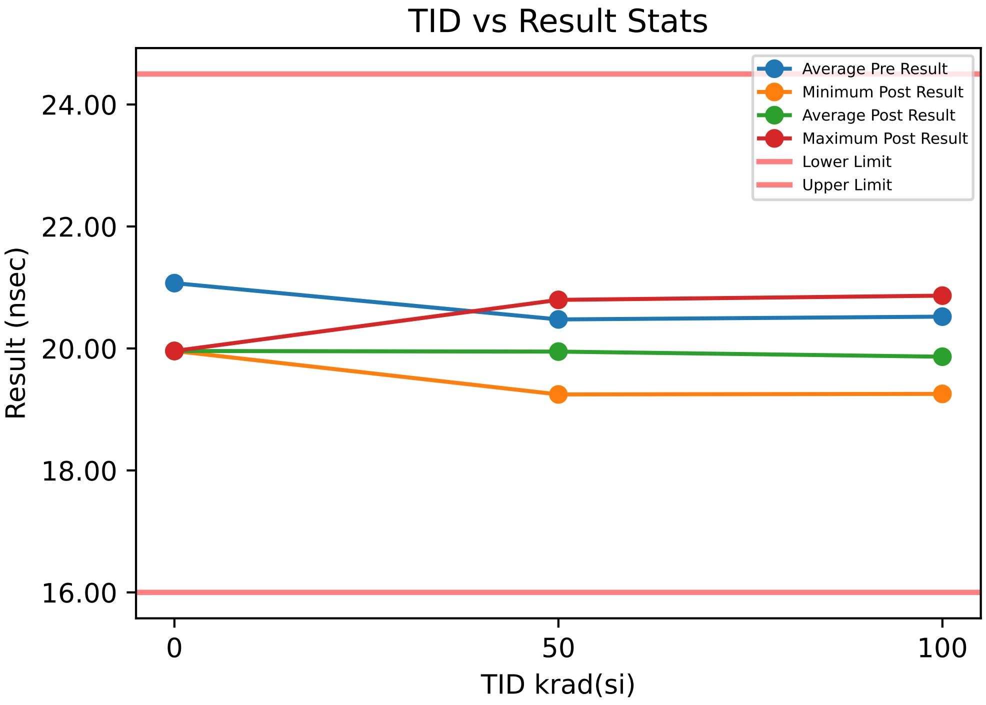
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

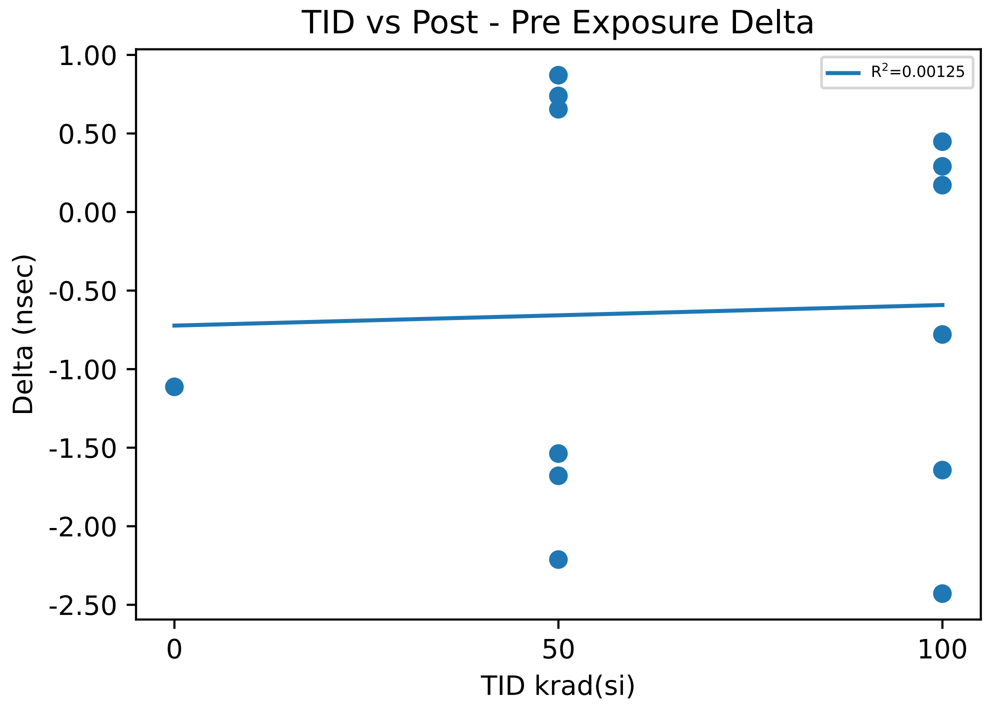
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	9.7363	10.675	0.9385
60	50	Biased	11.104	10.014	-1.09
61	50	Biased	9.387	10.603	1.216
63	100	Biased	9.6436	10.808	1.1647
64	100	Biased	11.234	10.112	-1.1219
65	100	Biased	9.8672	9.7405	-0.1267
66	50	Unbiased	11.355	9.8378	-1.5173
67	50	Unbiased	9.7156	10.906	1.1908
68	50	Unbiased	11.463	9.8163	-1.6472
69	100	Unbiased	10.424	11.28	0.8554
70	100	Unbiased	11.671	10.101	-1.5698
71	100	Unbiased	9.9445	10.833	0.8882
72	0	Control	10.857	9.8646	-0.9929

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.857	10.857	10.857		9.8646	9.8646	9.8646		-0.9929	-0.9929	-0.9929	
50	9.387	10.46	11.463	0.94369	9.8163	10.309	10.906	0.47511	-1.6472	-0.15153	1.216	1.4031
100	9.6436	10.464	11.671	0.81857	9.7405	10.479	11.28	0.58265	-1.5698	0.014983	1.1647	1.1502

Device Test: 95.31 DHL Dead Time Mid 2MHz VIN_10V





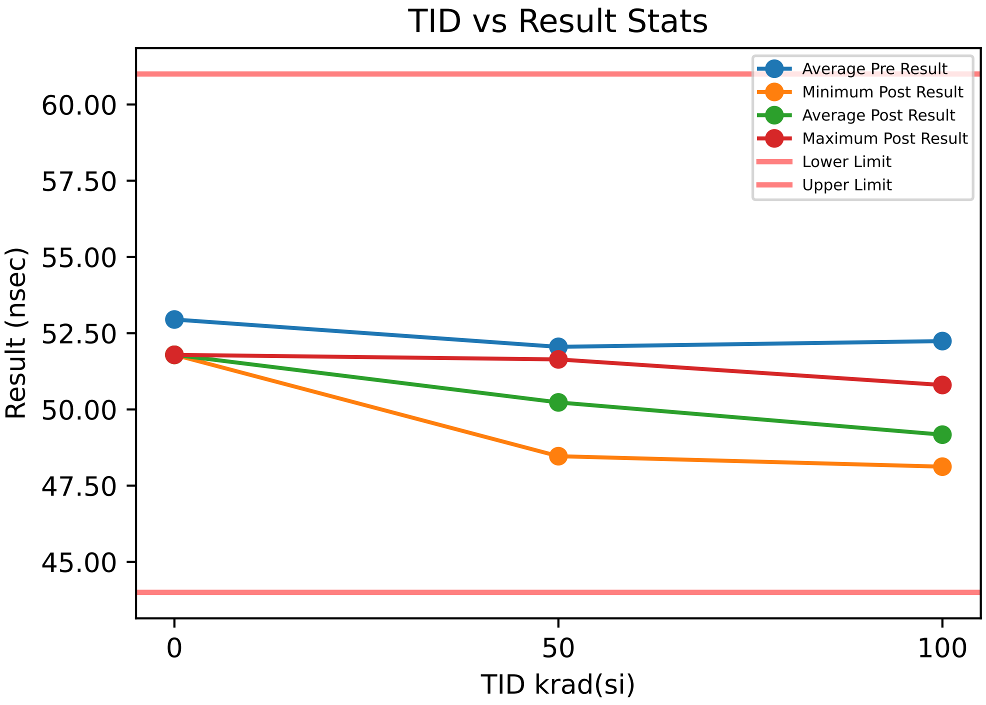
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

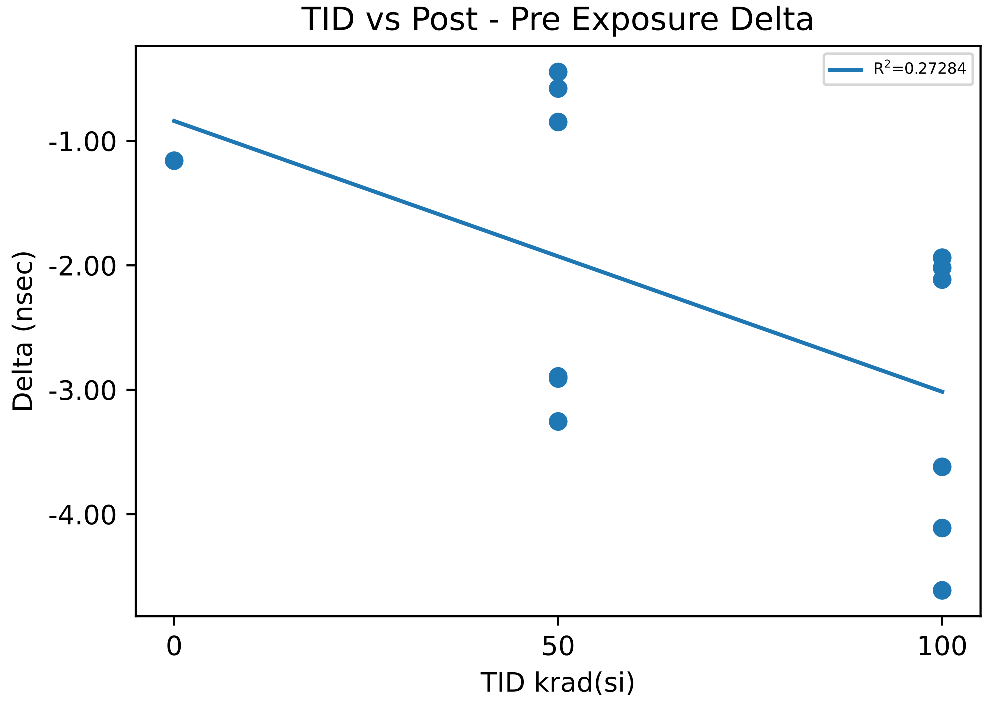
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	19.729	20.383	0.6542
60	50	Biased	21.088	19.551	-1.5374
61	50	Biased	19.66	20.398	0.7387
63	100	Biased	19.802	20.25	0.4479
64	100	Biased	20.996	19.353	-1.6426
65	100	Biased	20.053	19.273	-0.7794
66	50	Unbiased	20.925	19.246	-1.6789
67	50	Unbiased	19.925	20.796	0.8709
68	50	Unbiased	21.527	19.315	-2.2121
69	100	Unbiased	20.695	20.866	0.171
70	100	Unbiased	21.684	19.255	-2.4287
71	100	Unbiased	19.9	20.19	0.2906
72	0	Control	21.071	19.958	-1.1127

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.071	21.071	21.071		19.958	19.958	19.958		-1.1127	-1.1127	-1.1127	
50	19.66	20.476	21.527	0.80131	19.246	19.948	20.796	0.65753	-2.2121	-0.52743	0.8709	1.424
100	19.802	20.521	21.684	0.73895	19.255	19.865	20.866	0.66922	-2.4287	-0.65687	0.4479	1.1773

Device Test: 95.32 DHL Dead Time Large 2MHz VIN_10V





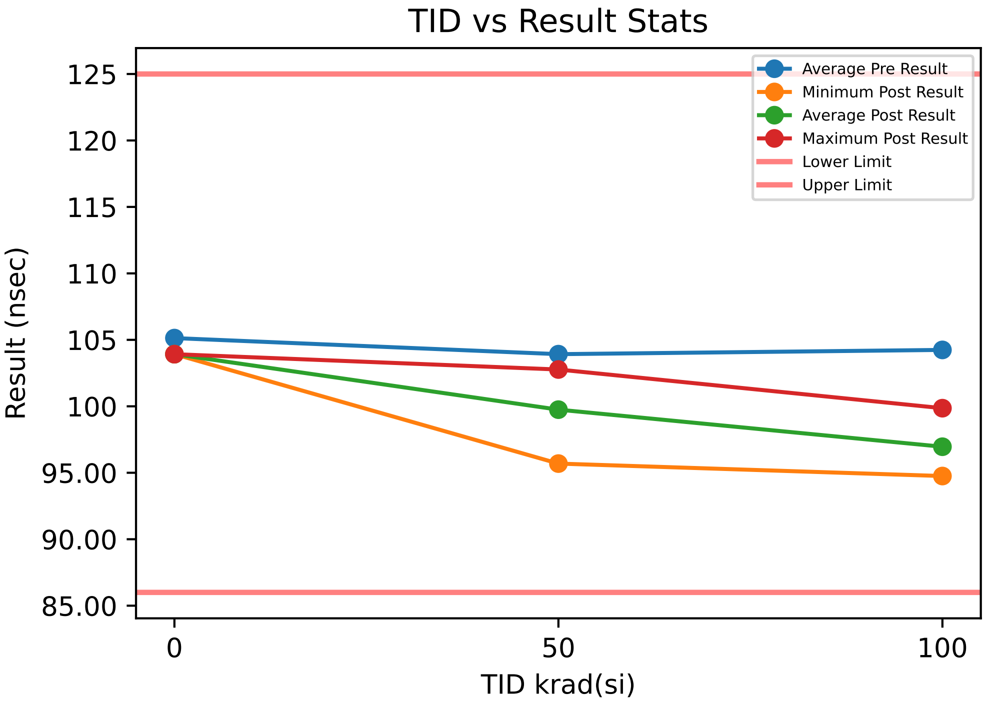
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

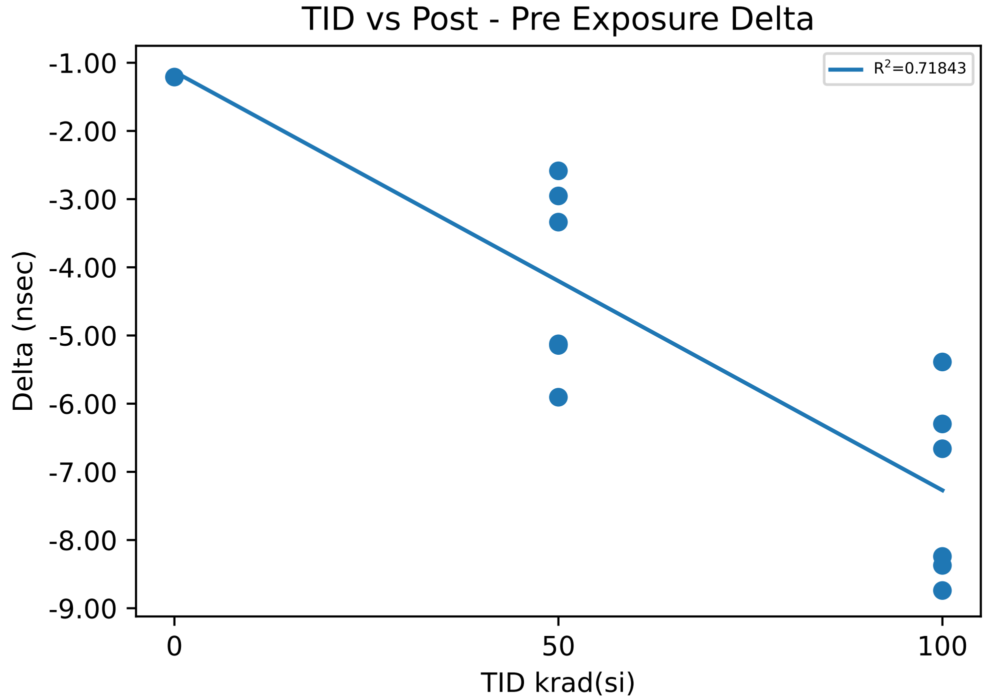
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	51.294	50.446	-0.8482
60	50	Biased	52.429	49.52	-2.9094
61	50	Biased	52.089	51.51	-0.579
63	100	Biased	51.899	49.88	-2.0197
64	100	Biased	52.234	48.123	-4.1109
65	100	Biased	52.408	48.789	-3.6193
66	50	Unbiased	51.359	48.467	-2.8929
67	50	Unbiased	52.087	51.641	-0.446
68	50	Unbiased	53.055	49.8	-3.2548
69	100	Unbiased	52.916	50.801	-2.1143
70	100	Unbiased	52.784	48.172	-4.6117
71	100	Unbiased	51.207	49.269	-1.9386
72	0	Control	52.949	51.79	-1.1591

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.949	52.949	52.949		51.79	51.79	51.79		-1.1591	-1.1591	-1.1591	
50	51.294	52.052	53.055	0.66412	48.467	50.23	51.641	1.2225	-3.2548	-1.8217	-0.446	1.3243
100	51.207	52.241	52.916	0.62666	48.123	49.172	50.801	1.0403	-4.6117	-3.0691	-1.9386	1.1882

Device Test: 95.33 DHL Dead Time Max 2MHz VIN_10V





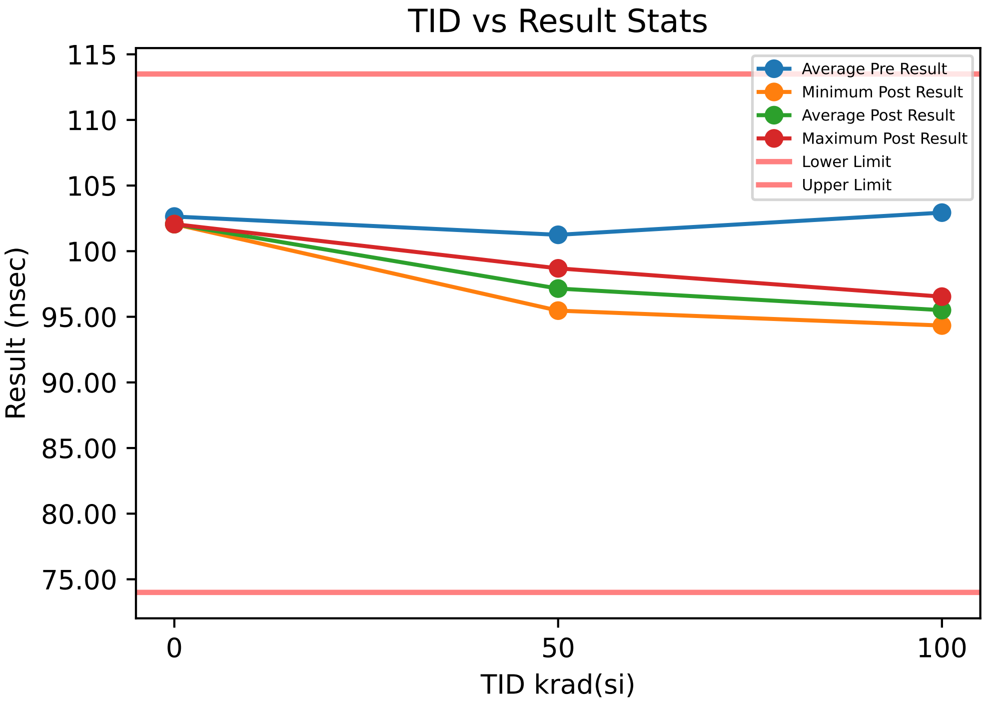
Test Results (Lower Limit = 86.0,
Upper Limit = 125.0 (nsec))

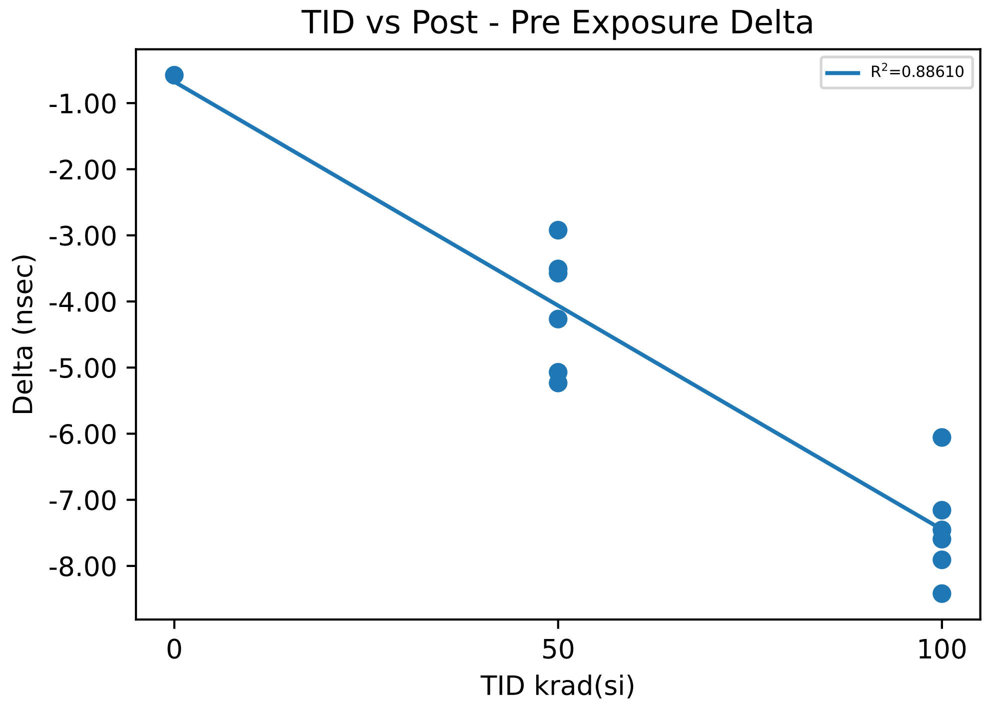
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	102.97	99.638	-3.3372
60	50	Biased	104.48	99.334	-5.1461
61	50	Biased	105.72	102.77	-2.9533
63	100	Biased	105.11	98.445	-6.661
64	100	Biased	103.21	94.84	-8.372
65	100	Biased	105.06	96.814	-8.2406
66	50	Unbiased	100.81	95.691	-5.1226
67	50	Unbiased	104.37	101.78	-2.5852
68	50	Unbiased	105.18	99.273	-5.9055
69	100	Unbiased	106.16	99.859	-6.2972
70	100	Unbiased	103.49	94.754	-8.7404
71	100	Unbiased	102.43	97.043	-5.3884
72	0	Control	105.13	103.92	-1.21

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	105.13	105.13	105.13		103.92	103.92	103.92		-1.21	-1.21	-1.21	
50	100.81	103.92	105.72	1.7827	95.691	99.748	102.77	2.455	-5.9055	-4.175	-2.5852	1.3826
100	102.43	104.24	106.16	1.4118	94.754	96.959	99.859	1.9996	-8.7404	-7.2833	-5.3884	1.3546

Device Test: 95.4 DLH Dead Time Max 500kMHz VIN_10V





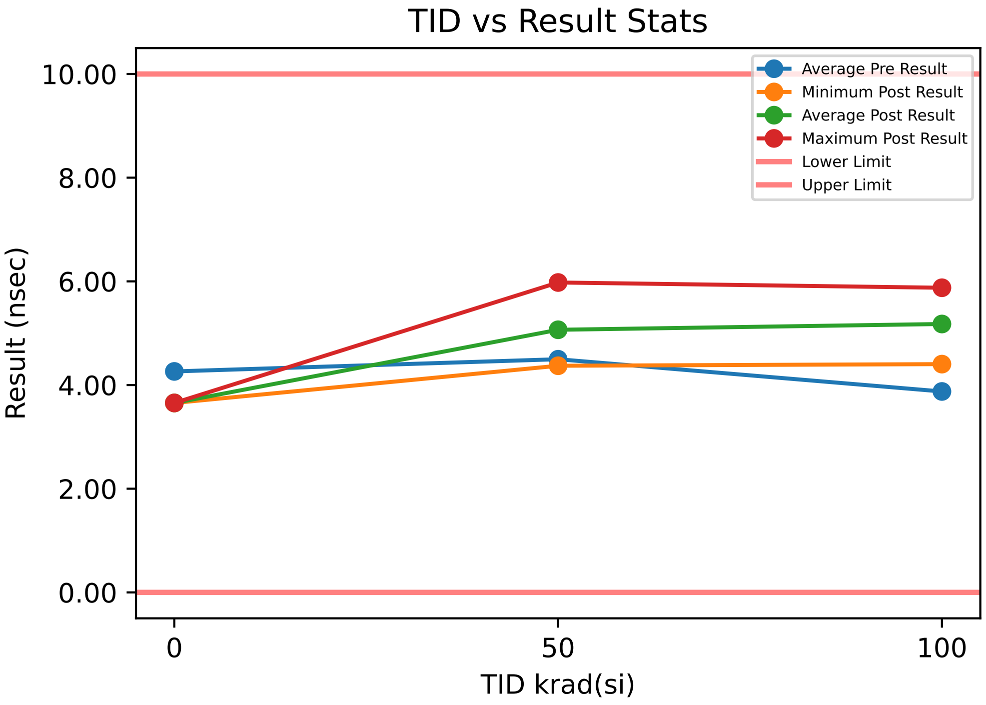
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	101.61	98.692	-2.9221
60	50	Biased	100.54	95.469	-5.0709
61	50	Biased	100.71	97.134	-3.5716
63	100	Biased	100.82	94.767	-6.0567
64	100	Biased	101.79	94.335	-7.4551
65	100	Biased	104.13	96.536	-7.5949
66	50	Unbiased	101.44	96.206	-5.2325
67	50	Unbiased	101.38	97.877	-3.5079
68	50	Unbiased	101.8	97.532	-4.2662
69	100	Unbiased	103.8	95.894	-7.9077
70	100	Unbiased	103.74	95.318	-8.4183
71	100	Unbiased	103.34	96.178	-7.1574
72	0	Control	102.64	102.06	-0.5781

Test Statistics (nsec)

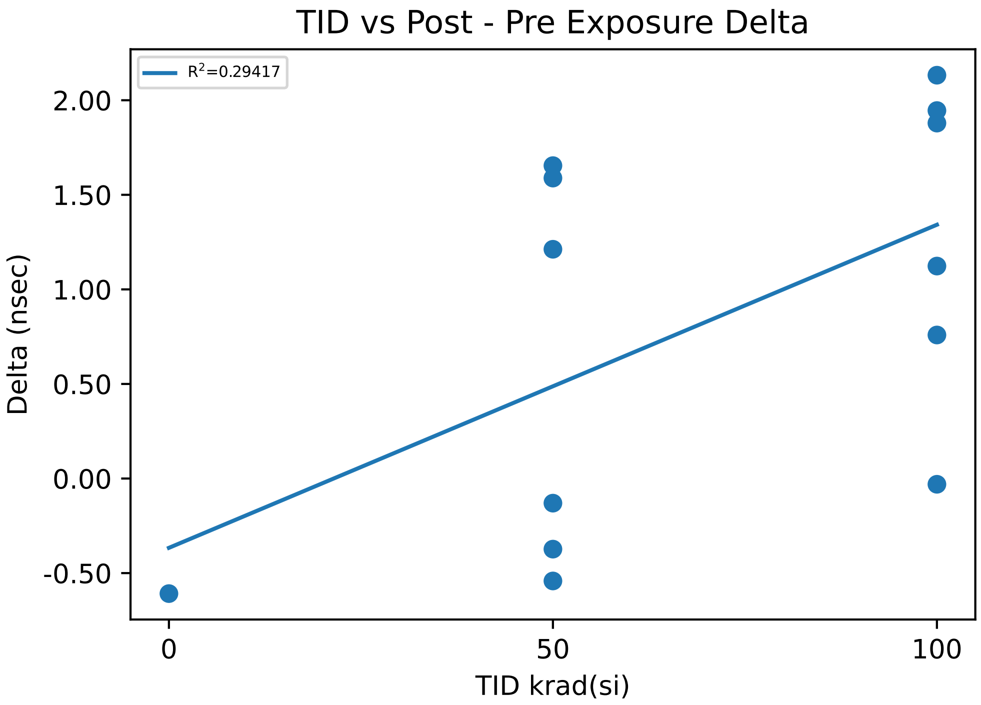
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	102.64	102.64	102.64		102.06	102.06	102.06		-0.5781	-0.5781	-0.5781	
50	100.54	101.25	101.8	0.50731	95.469	97.152	98.692	1.1635	-5.2325	-4.0952	-2.9221	0.92411
100	100.82	102.94	104.13	1.323	94.335	95.505	96.536	0.85041	-8.4183	-7.4317	-6.0567	0.79912

Device Test: 95.5 DLH Dead Time Min 1MHz VIN_10V



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

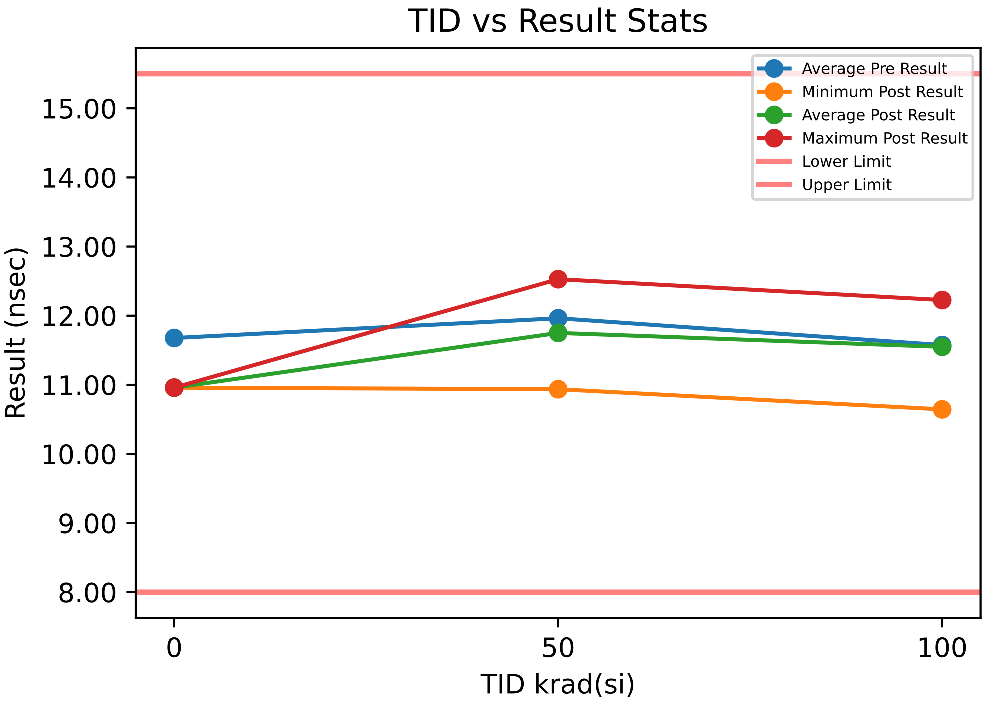
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.3237	5.978	1.6543
60	50	Biased	5.1071	4.5655	-0.5416
61	50	Biased	4.545	5.7571	1.2121
63	100	Biased	3.931	5.8765	1.9455
64	100	Biased	4.6181	5.7414	1.1233
65	100	Biased	3.6658	4.4247	0.7589
66	50	Unbiased	4.7453	4.372	-0.3733
67	50	Unbiased	3.4277	5.0162	1.5885
68	50	Unbiased	4.8376	4.7074	-0.1302
69	100	Unbiased	3.8111	5.6903	1.8792
70	100	Unbiased	4.4339	4.4035	-0.0304
71	100	Unbiased	2.7963	4.9287	2.1324
72	0	Control	4.2627	3.6543	-0.6084



Test Statistics (nsec)

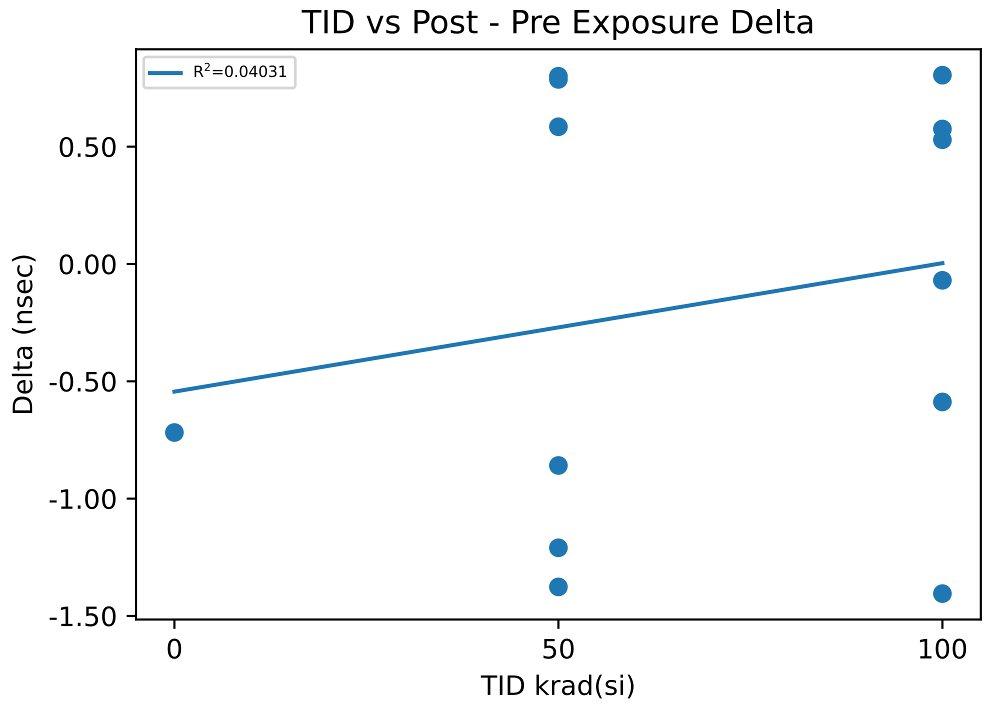
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.2627	4.2627	4.2627		3.6543	3.6543	3.6543		-0.6084	-0.6084	-0.6084	
50	3.4277	4.4977	5.1071	0.58747	4.372	5.066	5.978	0.65918	-0.5416	0.5683	1.6543	1.0238
100	2.7963	3.876	4.6181	0.64485	4.4035	5.1775	5.8765	0.67782	-0.0304	1.3015	2.1324	0.84131

Device Test: 95.6 DLH Dead Time Small 1MHz VIN_10V



Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

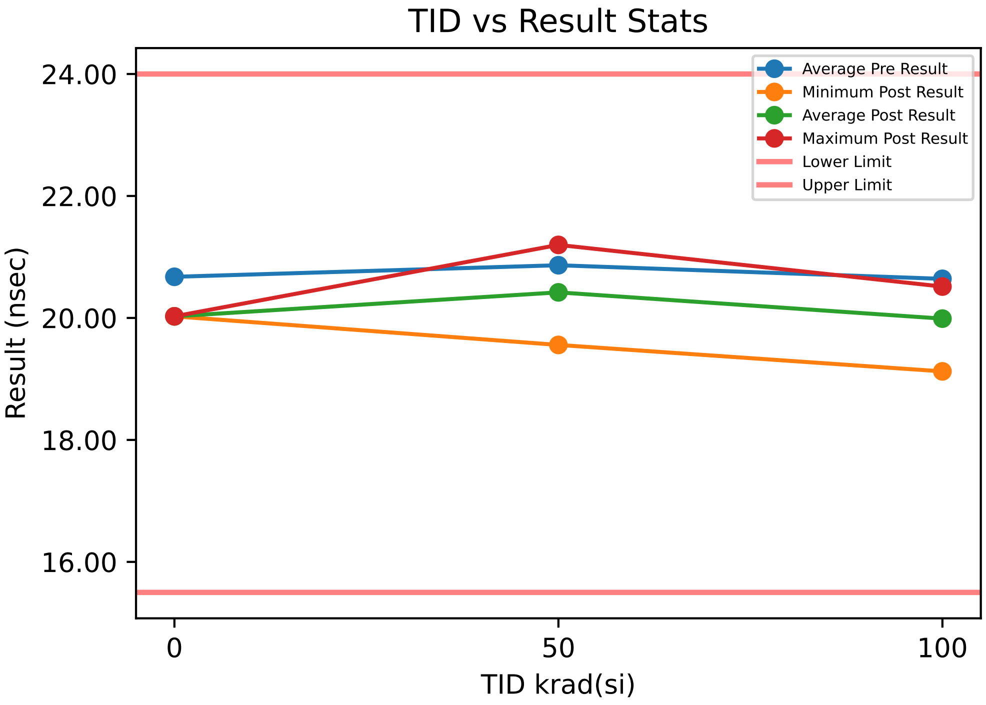
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	11.728	12.528	0.8002
60	50	Biased	12.312	10.936	-1.3762
61	50	Biased	11.838	12.422	0.5849
63	100	Biased	11.533	12.062	0.5295
64	100	Biased	12.042	11.972	-0.0696
65	100	Biased	11.569	10.981	-0.5879
66	50	Unbiased	12.301	11.092	-1.2095
67	50	Unbiased	11.147	11.933	0.7866
68	50	Unbiased	12.449	11.591	-0.8587
69	100	Unbiased	11.651	12.226	0.5754
70	100	Unbiased	12.049	10.645	-1.4047
71	100	Unbiased	10.606	11.411	0.8046
72	0	Control	11.677	10.959	-0.7182

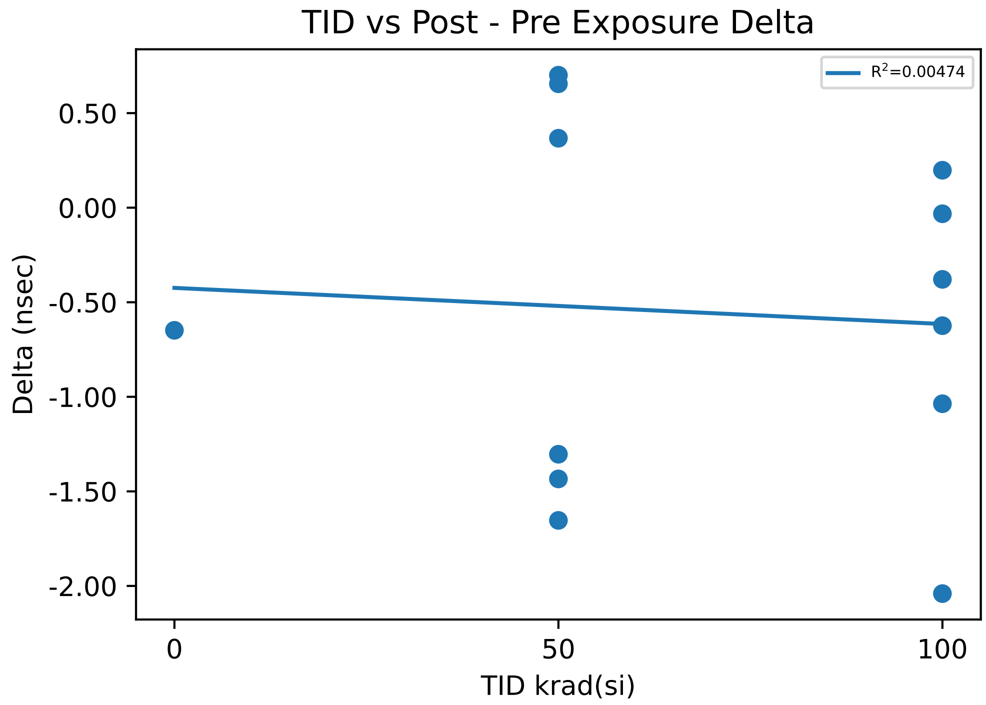


Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.677	11.677	11.677		10.959	10.959	10.959		-0.7182	-0.7182	-0.7182	
50	11.147	11.962	12.449	0.49199	10.936	11.75	12.528	0.6652	-1.3762	-0.21212	0.8002	1.0417
100	10.606	11.575	12.049	0.52718	10.645	11.549	12.226	0.64189	-1.4047	-0.02545	0.8046	0.846

Device Test: 95.7 DLH Dead Time Mid 1MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

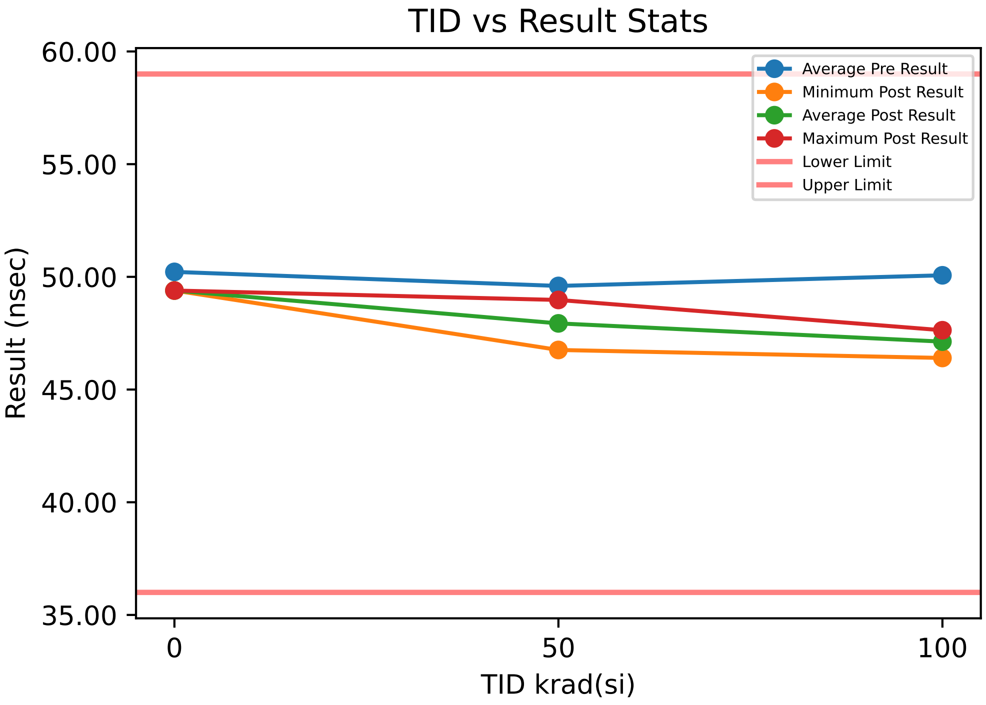
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

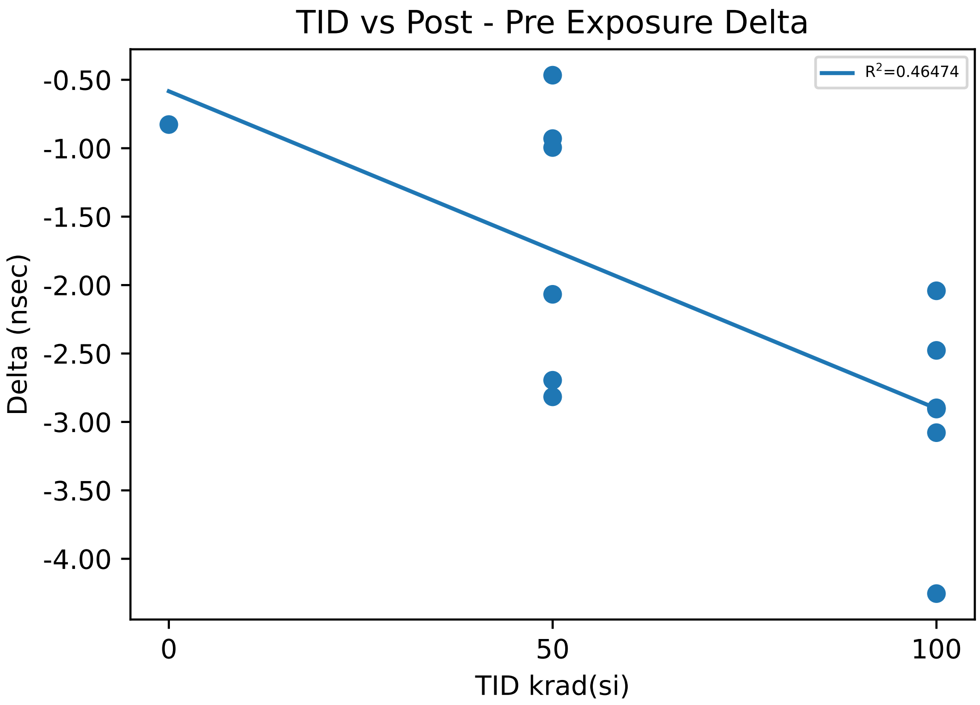
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	20.497	21.198	0.7005
60	50	Biased	21.211	19.558	-1.6535
61	50	Biased	20.768	21.135	0.3672
63	100	Biased	20.317	20.515	0.1981
64	100	Biased	20.893	20.269	-0.6239
65	100	Biased	20.808	19.772	-1.0366
66	50	Unbiased	21.188	19.754	-1.4342
67	50	Unbiased	20.142	20.797	0.6551
68	50	Unbiased	21.379	20.075	-1.3037
69	100	Unbiased	20.892	20.512	-0.379
70	100	Unbiased	21.164	19.124	-2.0405
71	100	Unbiased	19.773	19.741	-0.0321
72	0	Control	20.675	20.026	-0.6484

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.675	20.675	20.675		20.026	20.026	20.026		-0.6484	-0.6484	-0.6484	
50	20.142	20.864	21.379	0.4807	19.558	20.42	21.198	0.71624	-1.6535	-0.44477	0.7005	1.1277
100	19.773	20.641	21.164	0.50712	19.124	19.989	20.515	0.54507	-2.0405	-0.65233	0.1981	0.80723

Device Test: 95.8 DLH Dead Time Large 1MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

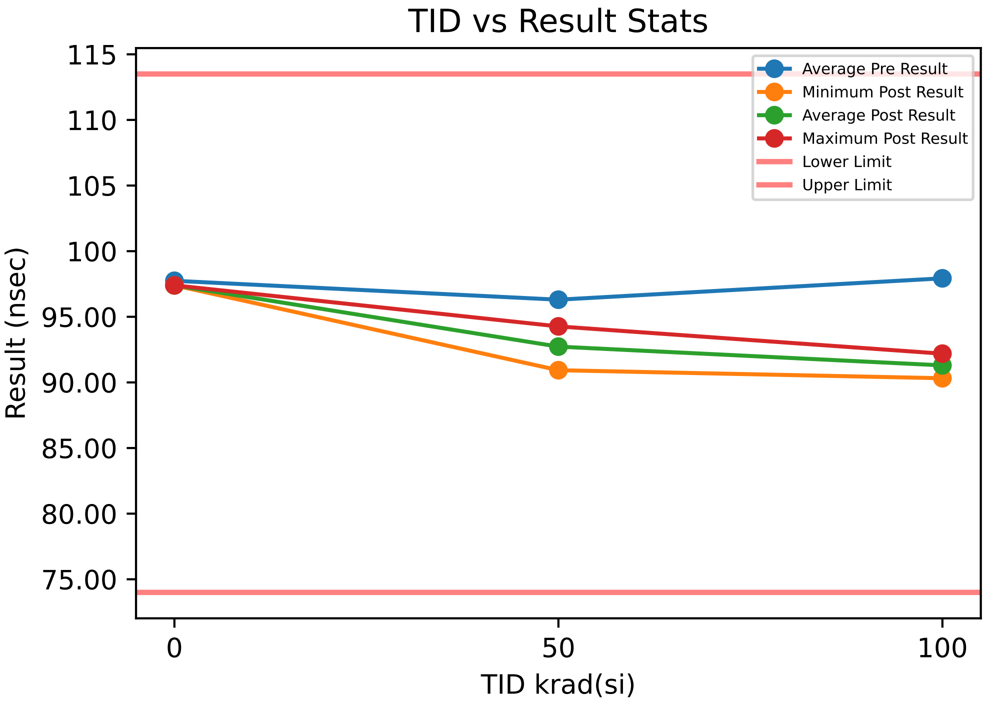
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

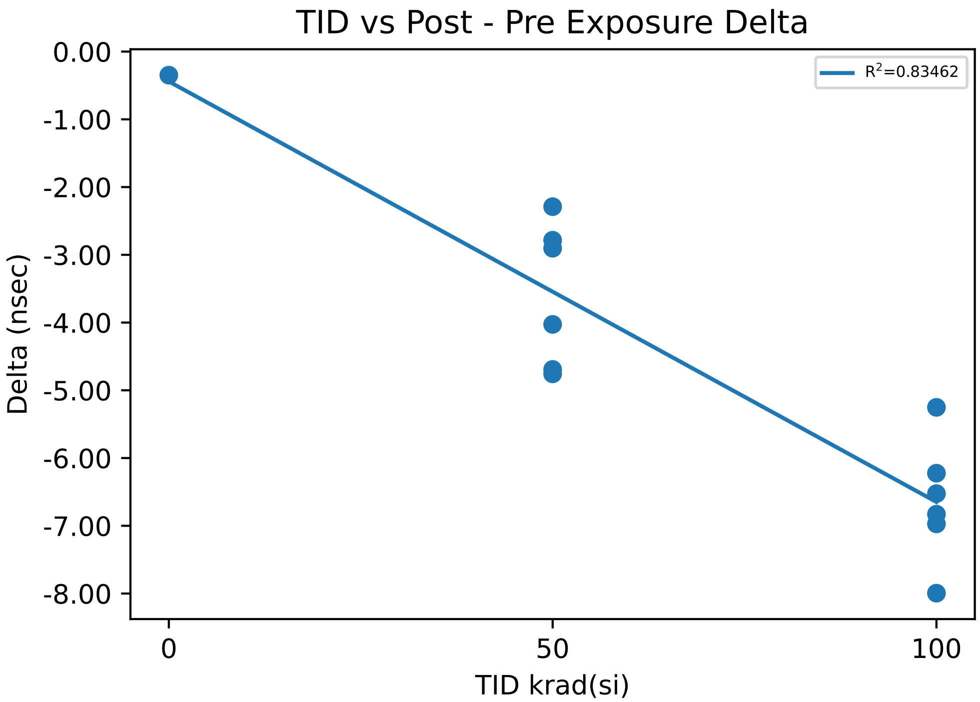
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	49.441	48.975	-0.4664
60	50	Biased	49.452	46.756	-2.6954
61	50	Biased	49.245	48.315	-0.9296
63	100	Biased	48.986	46.944	-2.0417
64	100	Biased	49.888	46.991	-2.897
65	100	Biased	50.621	47.542	-3.0784
66	50	Unbiased	50.087	47.271	-2.8166
67	50	Unbiased	49.384	48.389	-0.9948
68	50	Unbiased	49.974	47.906	-2.0675
69	100	Unbiased	50.537	47.632	-2.9058
70	100	Unbiased	50.656	46.401	-4.2543
71	100	Unbiased	49.725	47.248	-2.4773
72	0	Control	50.22	49.393	-0.827

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.22	50.22	50.22		49.393	49.393	49.393		-0.827	-0.827	-0.827	
50	49.245	49.597	50.087	0.34565	46.756	47.935	48.975	0.80794	-2.8166	-1.6617	-0.4664	0.99764
100	48.986	50.069	50.656	0.66229	46.401	47.126	47.632	0.45173	-4.2543	-2.9424	-2.0417	0.74439

Device Test: 95.9 DLH Dead Time Max 1MHz VIN_10V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

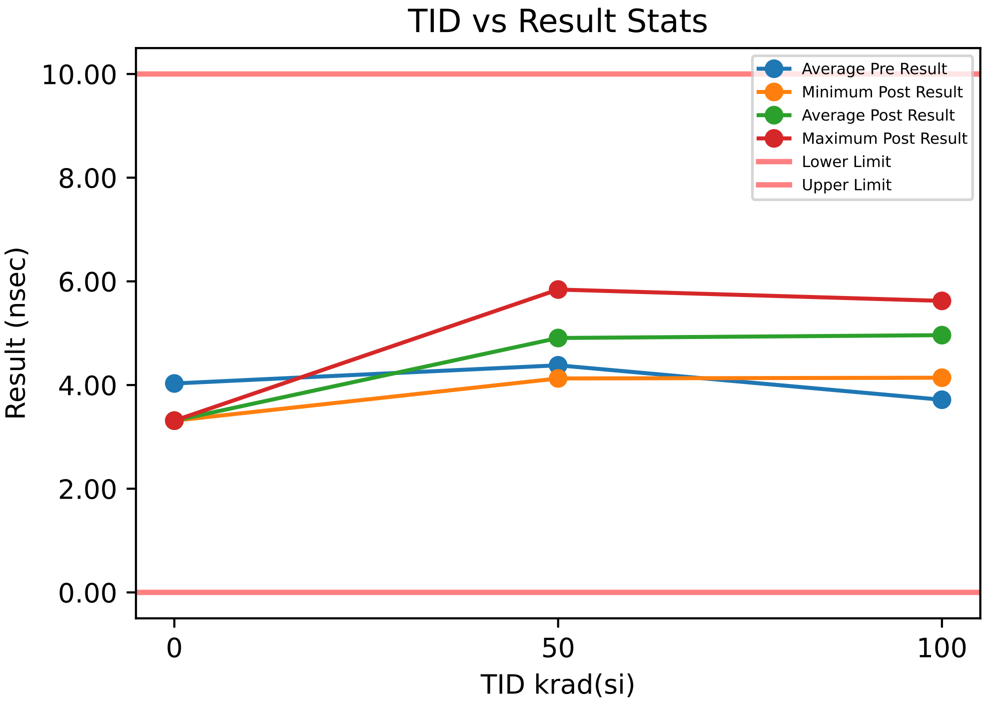
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

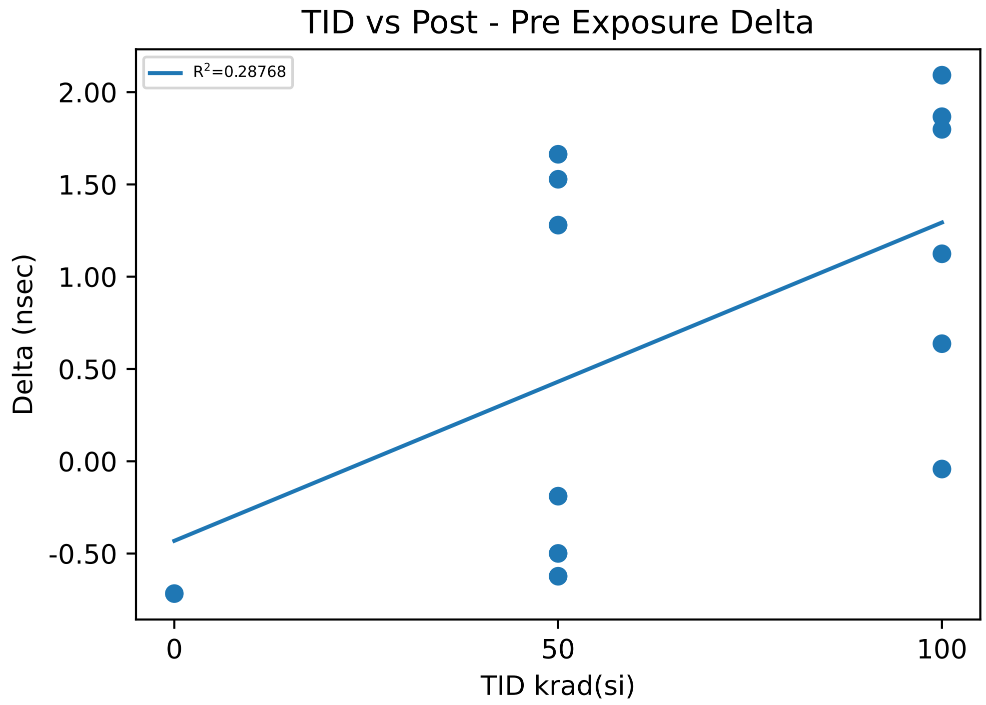
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	96.558	94.268	-2.2895
60	50	Biased	95.687	90.93	-4.7573
61	50	Biased	95.873	92.97	-2.9031
63	100	Biased	95.818	90.566	-5.2515
64	100	Biased	96.843	90.318	-6.5249
65	100	Biased	99.02	92.191	-6.8292
66	50	Unbiased	96.57	91.878	-4.6921
67	50	Unbiased	96.307	93.522	-2.7846
68	50	Unbiased	96.824	92.797	-4.027
69	100	Unbiased	98.75	91.778	-6.9715
70	100	Unbiased	98.801	90.807	-7.9947
71	100	Unbiased	98.351	92.128	-6.2236
72	0	Control	97.743	97.396	-0.3478

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.743	97.743	97.743		97.396	97.396	97.396		-0.3478	-0.3478	-0.3478	
50	95.687	96.303	96.824	0.44106	90.93	92.728	94.268	1.1852	-4.7573	-3.5756	-2.2895	1.0563
100	95.818	97.931	99.02	1.2992	90.318	91.298	92.191	0.83096	-7.9947	-6.6326	-5.2515	0.905

Device Test: 96.0 DLH Dead Time Min 500kHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

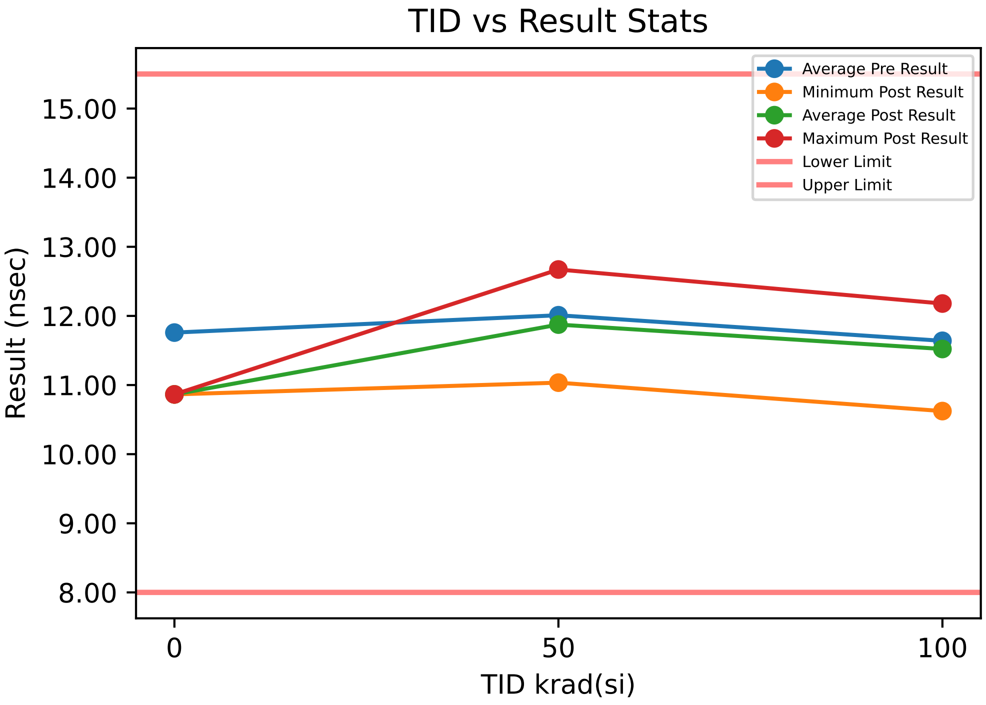
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

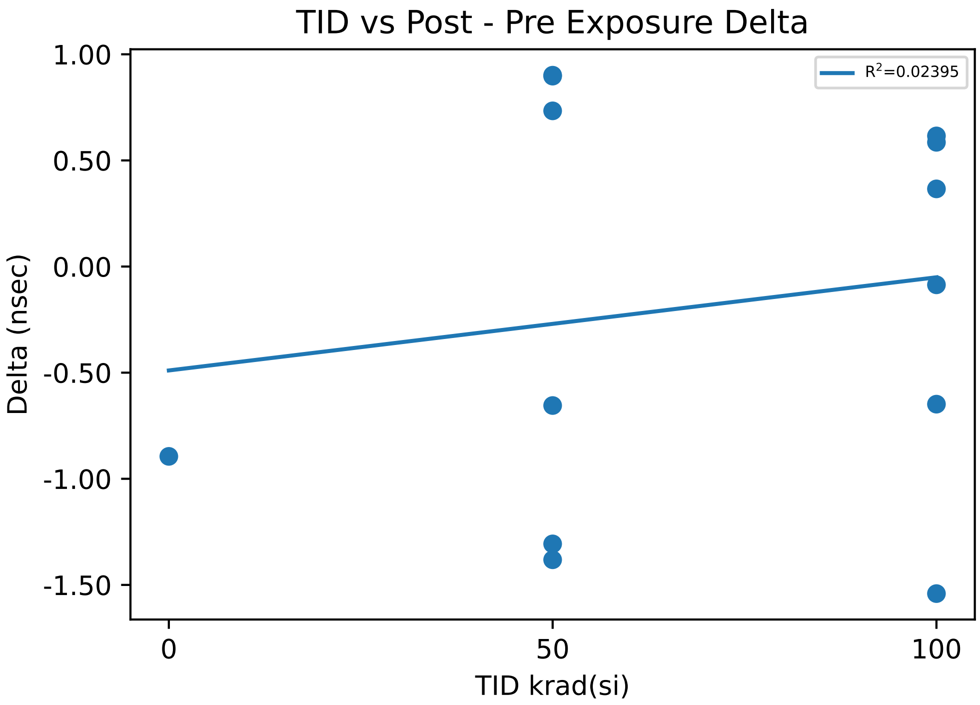
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.1791	5.8425	1.6634
60	50	Biased	5.009	4.3861	-0.6229
61	50	Biased	4.4295	5.709	1.2795
63	100	Biased	3.825	5.6234	1.7984
64	100	Biased	4.4515	5.5756	1.1241
65	100	Biased	3.5042	4.1412	0.637
66	50	Unbiased	4.6265	4.1272	-0.4993
67	50	Unbiased	3.315	4.843	1.528
68	50	Unbiased	4.7261	4.537	-0.1891
69	100	Unbiased	3.6749	5.5418	1.8669
70	100	Unbiased	4.2257	4.1836	-0.0421
71	100	Unbiased	2.6156	4.7074	2.0918
72	0	Control	4.0302	3.3132	-0.717

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0302	4.0302	4.0302		3.3132	3.3132	3.3132		-0.717	-0.717	-0.717	
50	3.315	4.3809	5.009	0.59215	4.1272	4.9075	5.8425	0.71257	-0.6229	0.5266	1.6634	1.0722
100	2.6156	3.7162	4.4515	0.64344	4.1412	4.9622	5.6234	0.70634	-0.0421	1.246	2.0918	0.83078

Device Test: 96.1 DLH Dead Time Small 500kHz VIN_12V





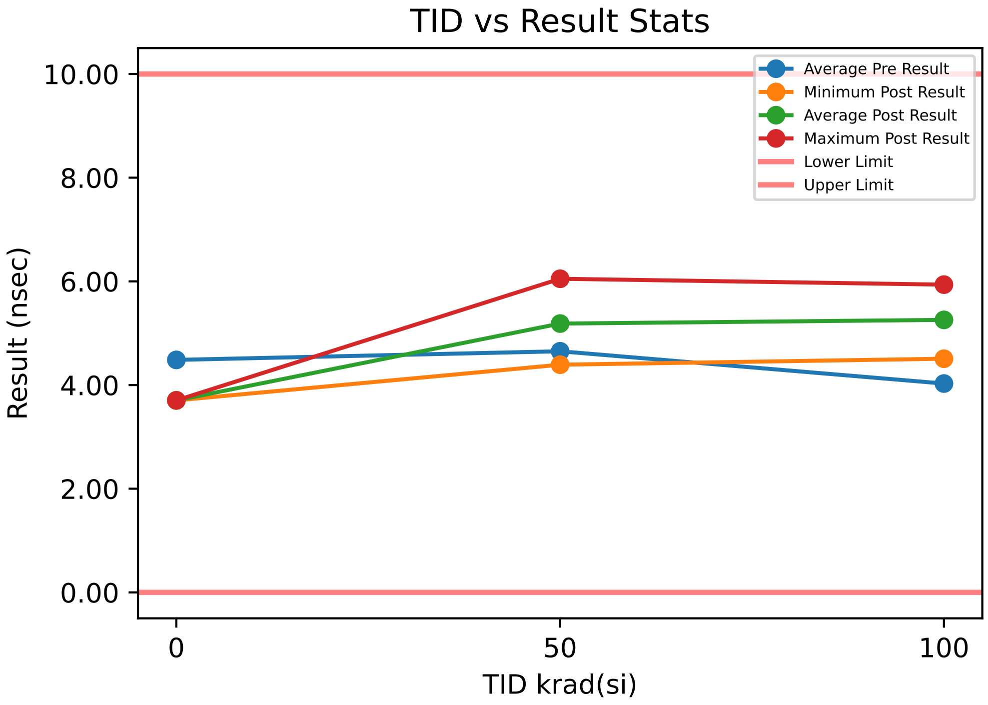
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

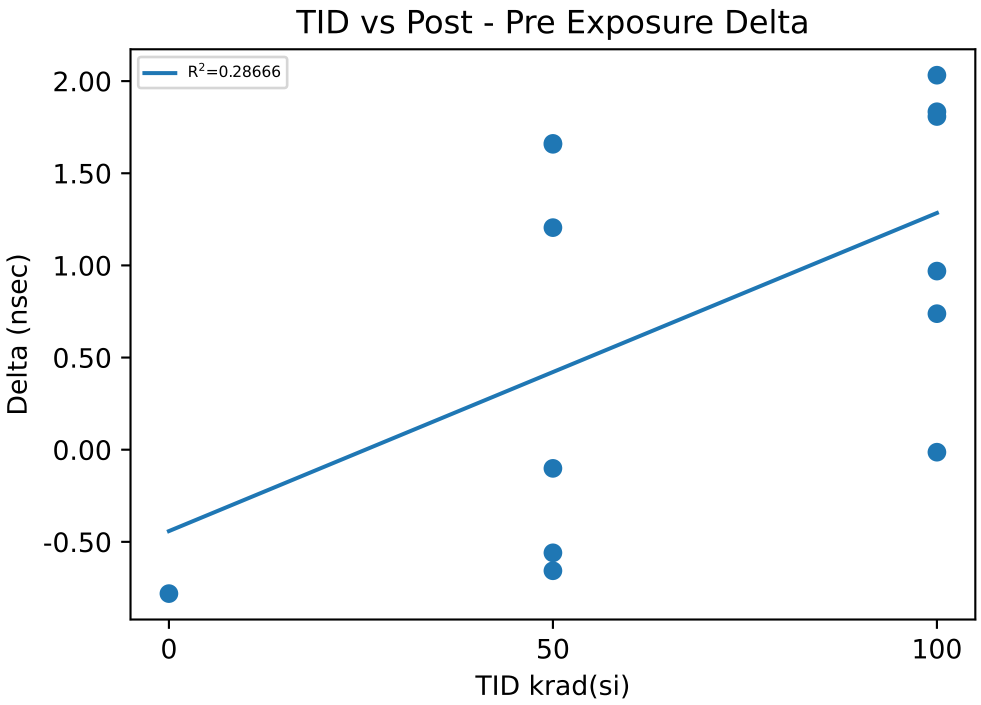
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	11.715	12.612	0.8971
60	50	Biased	12.416	11.034	-1.3815
61	50	Biased	11.938	12.672	0.7335
63	100	Biased	11.564	12.179	0.6154
64	100	Biased	12.032	11.946	-0.0861
65	100	Biased	11.669	11.021	-0.6484
66	50	Unbiased	12.373	11.066	-1.3067
67	50	Unbiased	11.118	12.02	0.9015
68	50	Unbiased	12.499	11.844	-0.6548
69	100	Unbiased	11.711	12.077	0.3659
70	100	Unbiased	12.164	10.623	-1.5409
71	100	Unbiased	10.698	11.284	0.5853
72	0	Control	11.759	10.864	-0.8944

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.759	11.759	11.759		10.864	10.864	10.864		-0.8944	-0.8944	-0.8944	
50	11.118	12.01	12.499	0.5336	11.034	11.875	12.672	0.71554	-1.3815	-0.13515	0.9015	1.1037
100	10.698	11.64	12.164	0.51515	10.623	11.522	12.179	0.63809	-1.5409	-0.11813	0.6154	0.84542

Device Test: 96.10 DLH Dead Time Min 2MHz VIN_12V





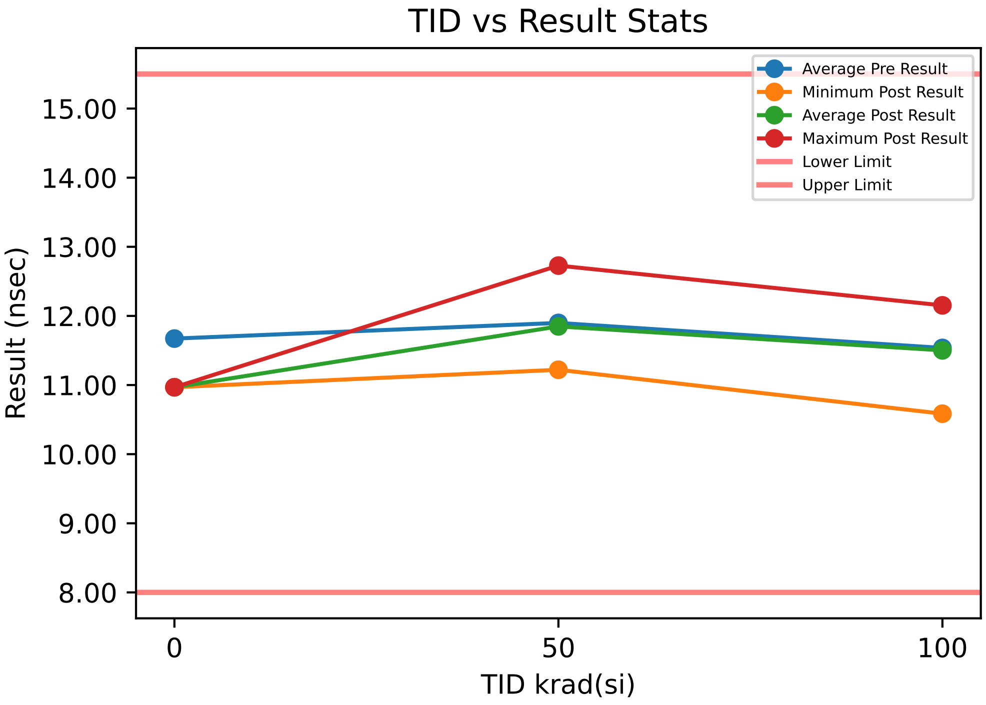
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

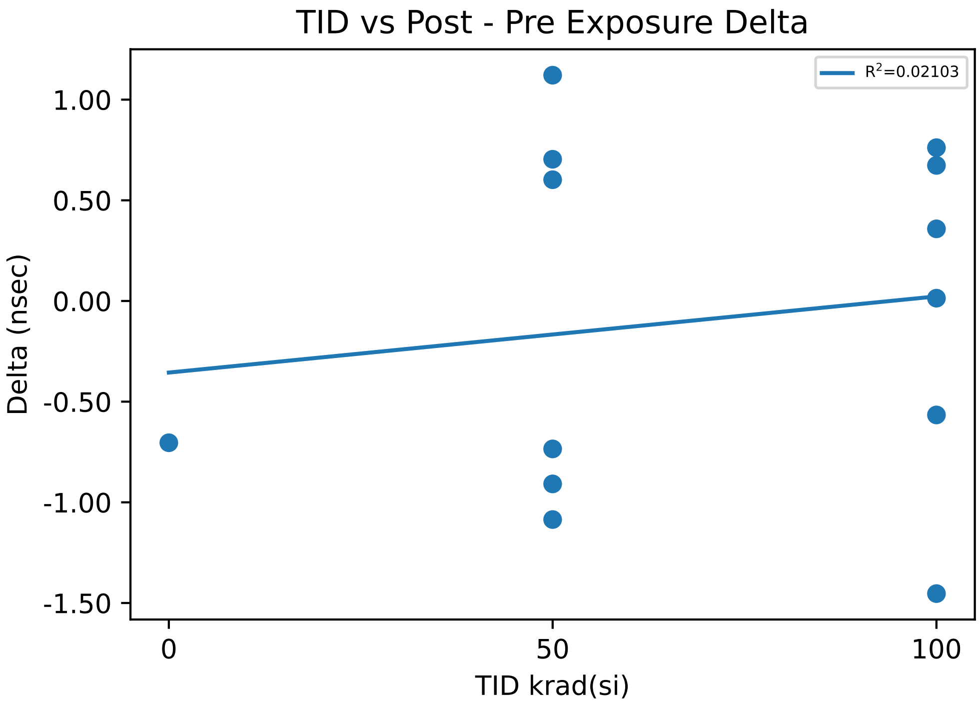
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.3881	6.0502	1.6621
60	50	Biased	5.2878	4.6309	-0.6569
61	50	Biased	4.6988	5.9038	1.205
63	100	Biased	4.1029	5.9367	1.8338
64	100	Biased	4.8586	5.8278	0.9692
65	100	Biased	3.8452	4.5833	0.7381
66	50	Unbiased	4.9517	4.3922	-0.5595
67	50	Unbiased	3.5583	5.2154	1.6571
68	50	Unbiased	5.0235	4.9222	-0.1013
69	100	Unbiased	3.9413	5.7492	1.8079
70	100	Unbiased	4.5211	4.5076	-0.0135
71	100	Unbiased	2.9032	4.9353	2.0321
72	0	Control	4.4849	3.7041	-0.7808

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4849	4.4849	4.4849		3.7041	3.7041	3.7041		-0.7808	-0.7808	-0.7808	
50	3.5583	4.6514	5.2878	0.61646	4.3922	5.1858	6.0502	0.67391	-0.6569	0.53442	1.6621	1.0956
100	2.9032	4.0287	4.8586	0.67004	4.5076	5.2566	5.9367	0.6556	-0.0135	1.2279	2.0321	0.79977

Device Test: 96.11 DLH Dead Time Small 2MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

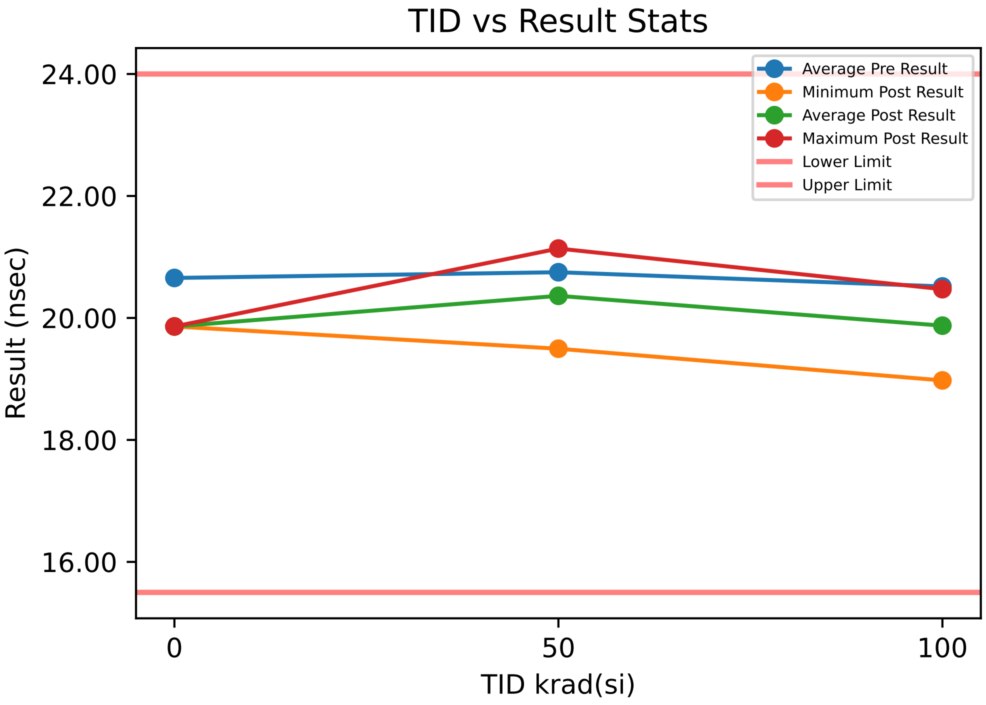
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

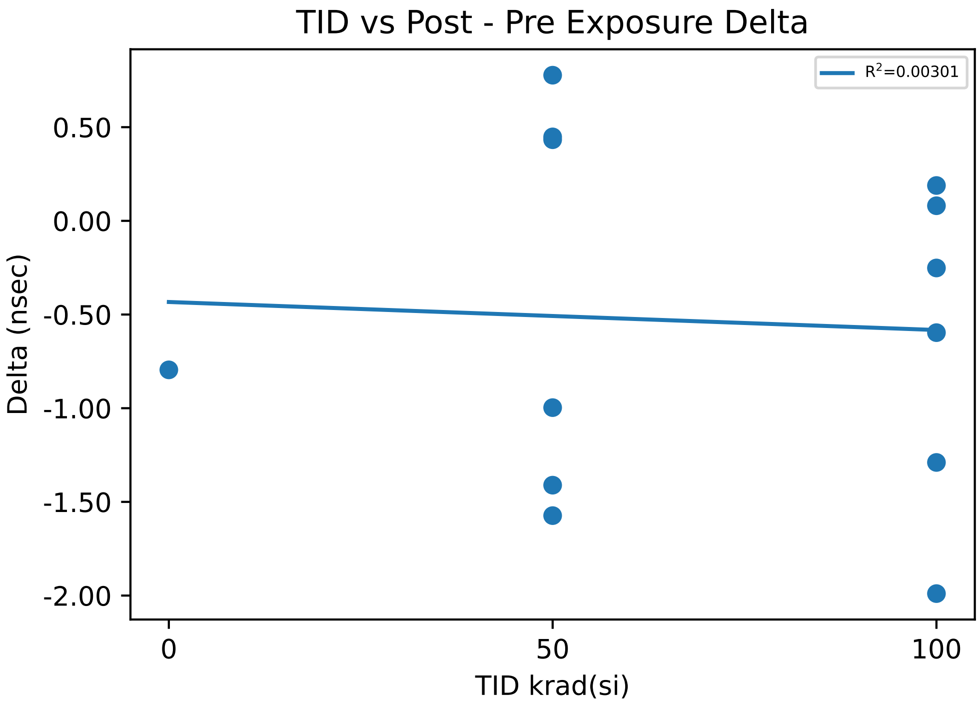
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	11.607	12.728	1.1214
60	50	Biased	12.306	11.221	-1.0855
61	50	Biased	11.863	12.465	0.6023
63	100	Biased	11.479	12.153	0.6734
64	100	Biased	11.956	11.97	0.0139
65	100	Biased	11.589	11.023	-0.566
66	50	Unbiased	12.191	11.282	-0.9085
67	50	Unbiased	11.119	11.823	0.7039
68	50	Unbiased	12.305	11.571	-0.7347
69	100	Unbiased	11.596	11.954	0.3583
70	100	Unbiased	12.039	10.585	-1.4533
71	100	Unbiased	10.562	11.323	0.7615
72	0	Control	11.672	10.968	-0.7041

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.672	11.672	11.672		10.968	10.968	10.968		-0.7041	-0.7041	-0.7041	
50	11.119	11.899	12.306	0.47135	11.221	11.848	12.728	0.624	-1.0855	-0.050183	1.1214	0.96376
100	10.562	11.537	12.039	0.52676	10.585	11.502	12.153	0.62432	-1.4533	-0.035367	0.7615	0.84698

Device Test: 96.12 DLH Dead Time Mid 2MHz VIN_12V





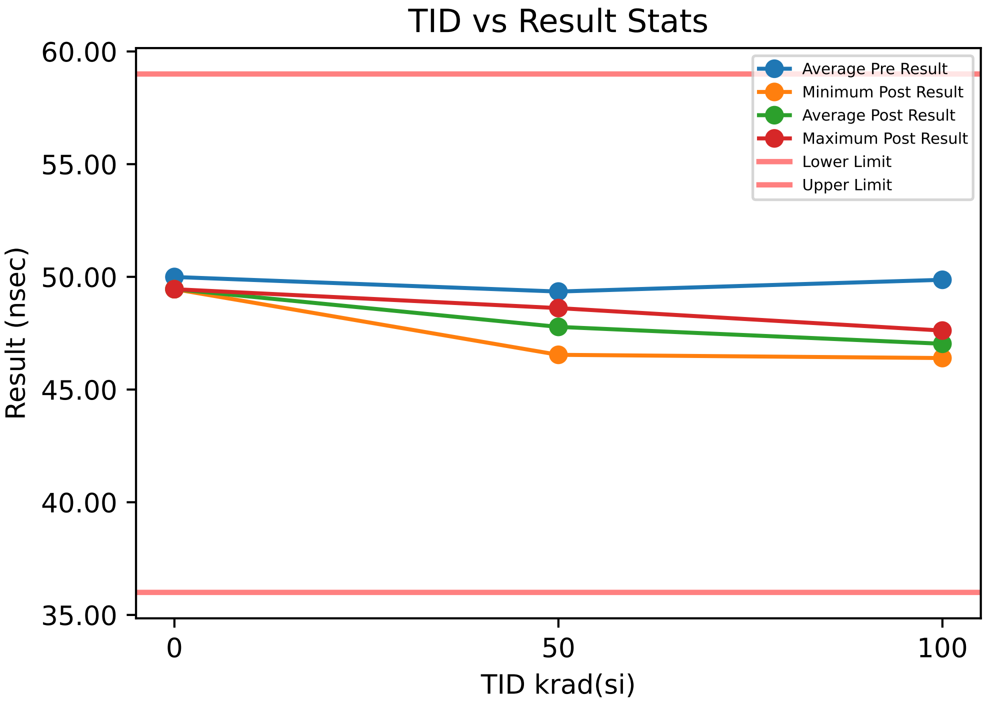
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

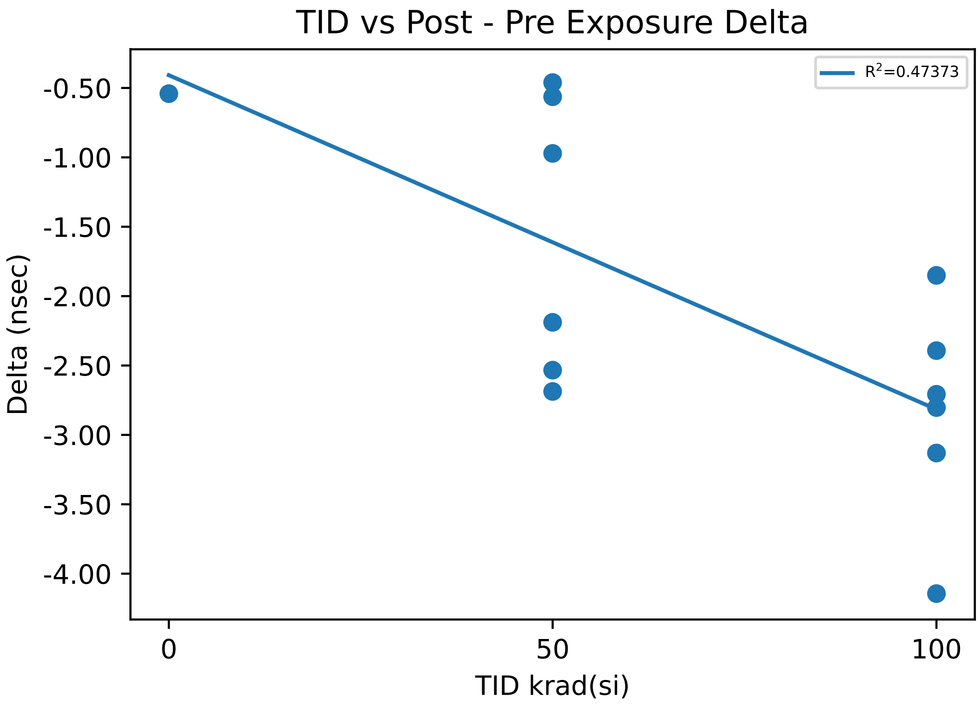
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	20.361	21.138	0.7774
60	50	Biased	21.069	19.495	-1.5733
61	50	Biased	20.567	21.015	0.4481
63	100	Biased	20.134	20.323	0.1887
64	100	Biased	20.858	20.261	-0.5967
65	100	Biased	20.768	19.479	-1.2895
66	50	Unbiased	21.125	19.714	-1.4108
67	50	Unbiased	20.108	20.541	0.433
68	50	Unbiased	21.27	20.273	-0.9969
69	100	Unbiased	20.723	20.472	-0.2515
70	100	Unbiased	20.965	18.976	-1.9895
71	100	Unbiased	19.651	19.732	0.0807
72	0	Control	20.656	19.86	-0.7953

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.656	20.656	20.656		19.86	19.86	19.86		-0.7953	-0.7953	-0.7953	
50	20.108	20.75	21.27	0.47108	19.495	20.363	21.138	0.66922	-1.5733	-0.38708	0.7774	1.0539
100	19.651	20.517	20.965	0.51374	18.976	19.874	20.472	0.58177	-1.9895	-0.64297	0.1887	0.84875

Device Test: 96.13 DLH Dead Time Large 2MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

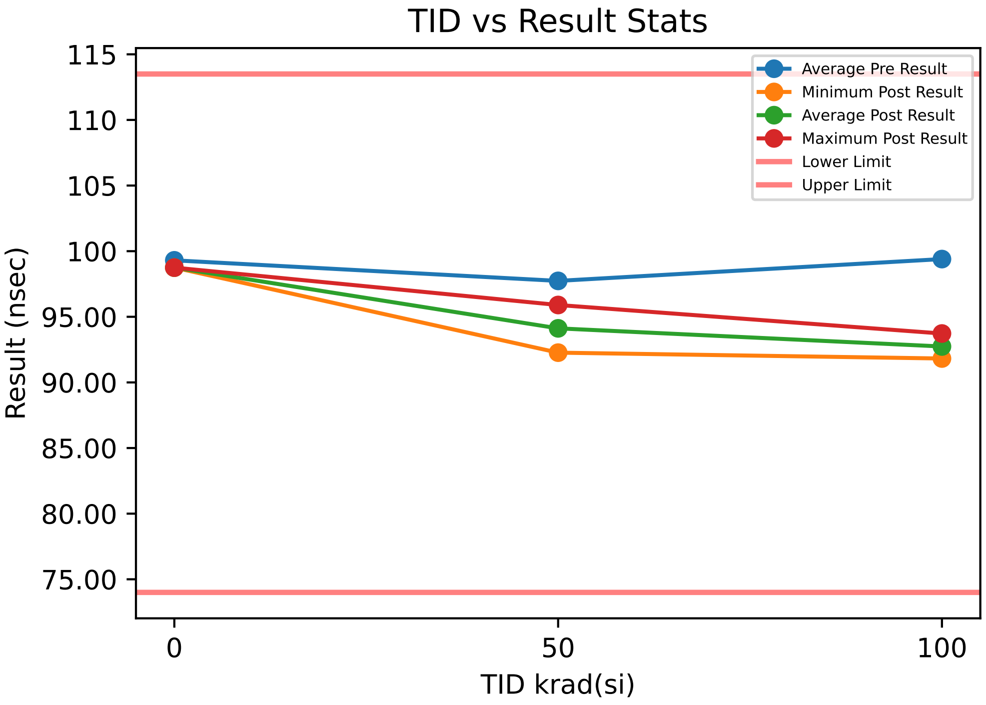
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

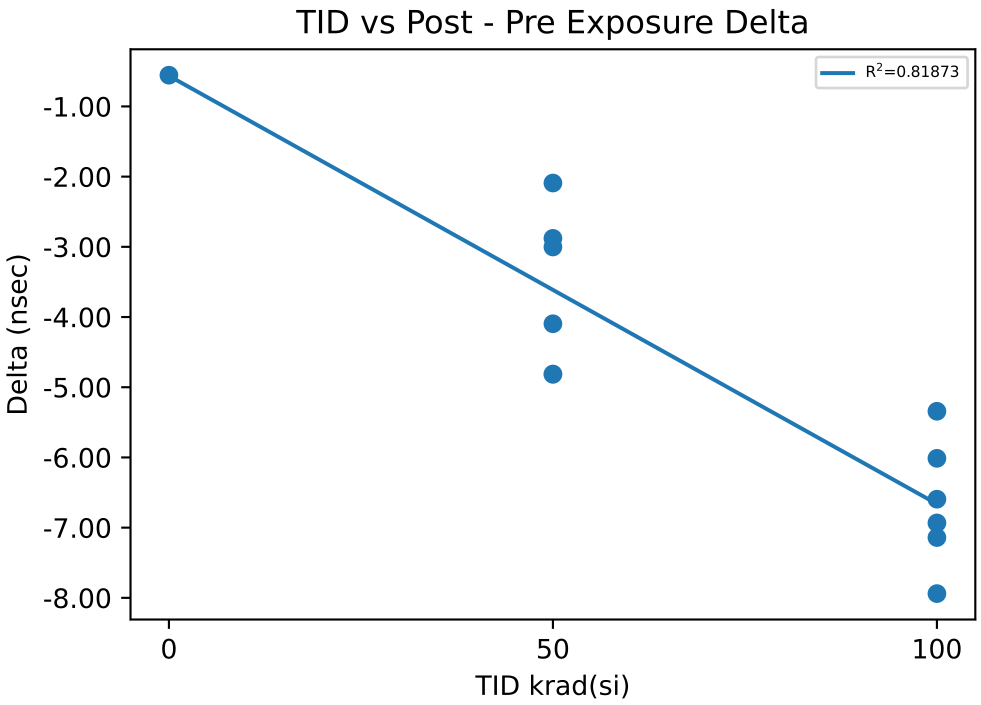
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	49.075	48.614	-0.4612
60	50	Biased	49.228	46.541	-2.687
61	50	Biased	49.084	48.112	-0.9716
63	100	Biased	48.733	46.882	-1.8505
64	100	Biased	49.661	46.858	-2.8031
65	100	Biased	50.418	47.288	-3.1306
66	50	Unbiased	49.854	47.321	-2.5334
67	50	Unbiased	49.101	48.538	-0.5632
68	50	Unbiased	49.745	47.556	-2.1888
69	100	Unbiased	50.324	47.617	-2.7072
70	100	Unbiased	50.541	46.398	-4.1436
71	100	Unbiased	49.538	47.146	-2.3926
72	0	Control	49.994	49.453	-0.541

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.994	49.994	49.994		49.453	49.453	49.453		-0.541	-0.541	-0.541	
50	49.075	49.348	49.854	0.35604	46.541	47.78	48.614	0.79693	-2.687	-1.5675	-0.4612	1.0159
100	48.733	49.869	50.541	0.69343	46.398	47.031	47.617	0.41835	-4.1436	-2.8379	-1.8505	0.77228

Device Test: 96.14 DLH Dead Time Max 2MHz VIN_12V





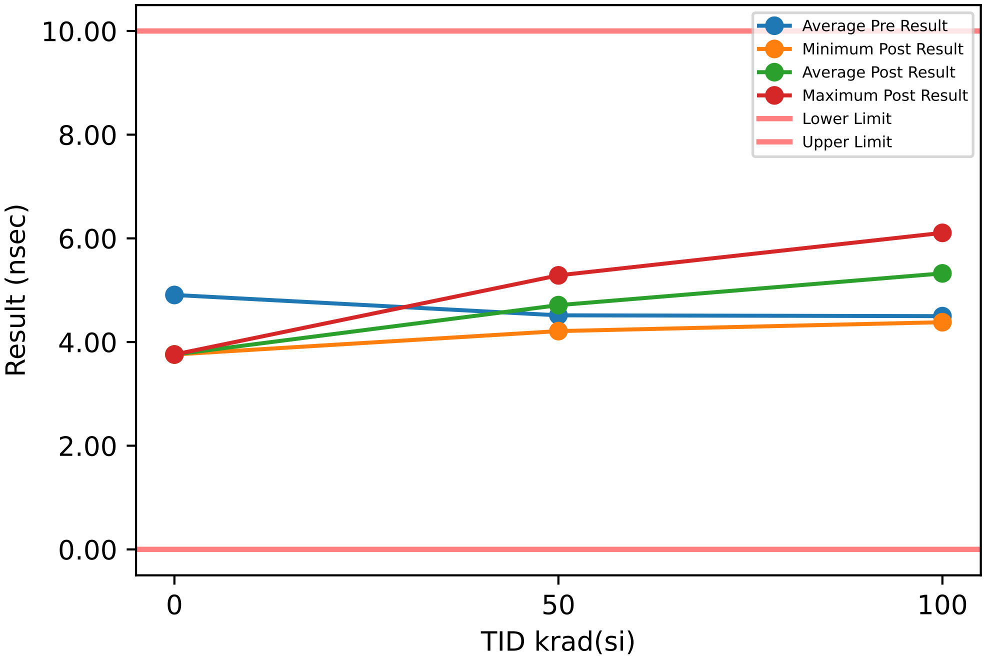
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

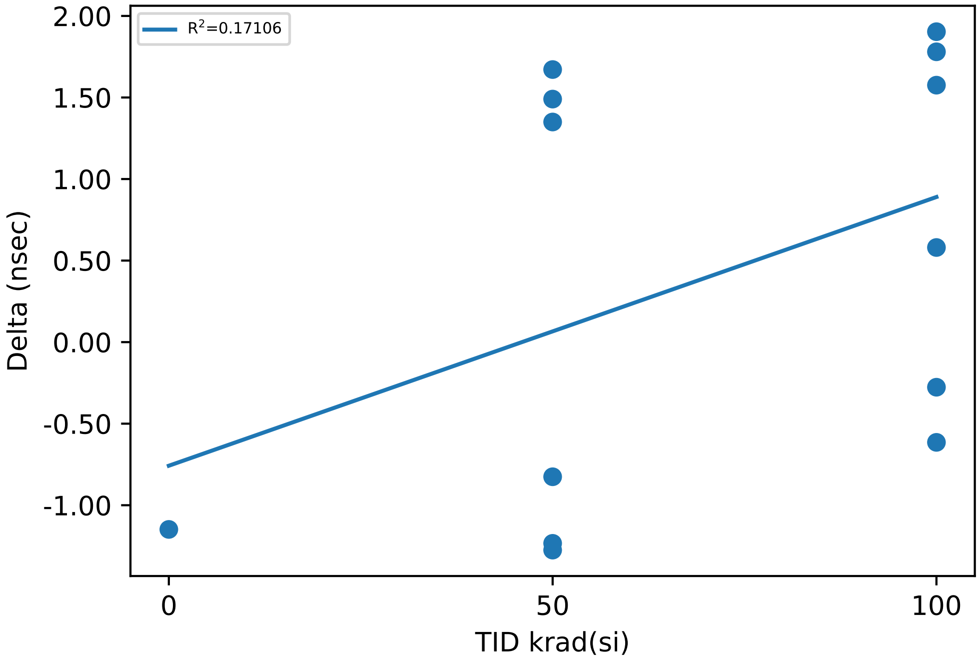
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	97.99	95.899	-2.0911
60	50	Biased	97.079	92.268	-4.8116
61	50	Biased	97.198	94.196	-3.002
63	100	Biased	97.268	91.926	-5.3422
64	100	Biased	98.416	91.822	-6.5947
65	100	Biased	100.55	93.62	-6.9328
66	50	Unbiased	98.089	93.273	-4.8168
67	50	Unbiased	97.819	94.939	-2.8795
68	50	Unbiased	98.24	94.144	-4.0957
69	100	Unbiased	100.2	93.058	-7.1409
70	100	Unbiased	100.21	92.271	-7.9395
71	100	Unbiased	99.739	93.726	-6.0127
72	0	Control	99.303	98.747	-0.5552

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.303	99.303	99.303		98.747	98.747	98.747		-0.5552	-0.5552	-0.5552	
50	97.079	97.736	98.24	0.48401	92.268	94.12	95.899	1.2642	-4.8168	-3.6161	-2.0911	1.1266
100	97.268	99.398	100.55	1.2847	91.822	92.737	93.726	0.84546	-7.9395	-6.6605	-5.3422	0.90583

Device Test: 96.19 DHL Dead Time Min 500kHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

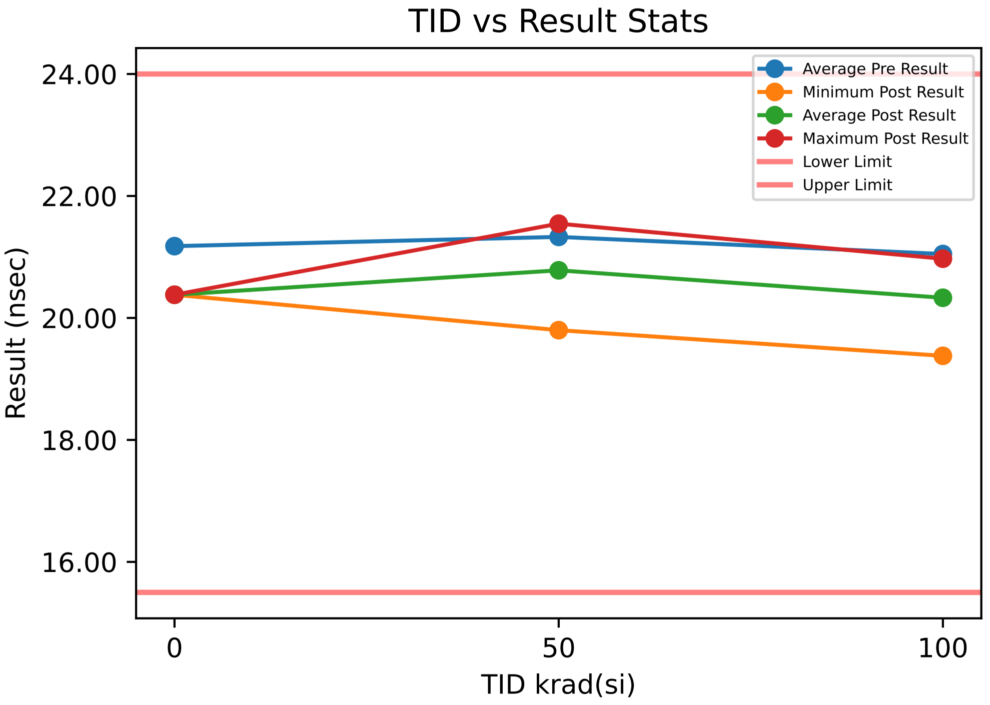
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

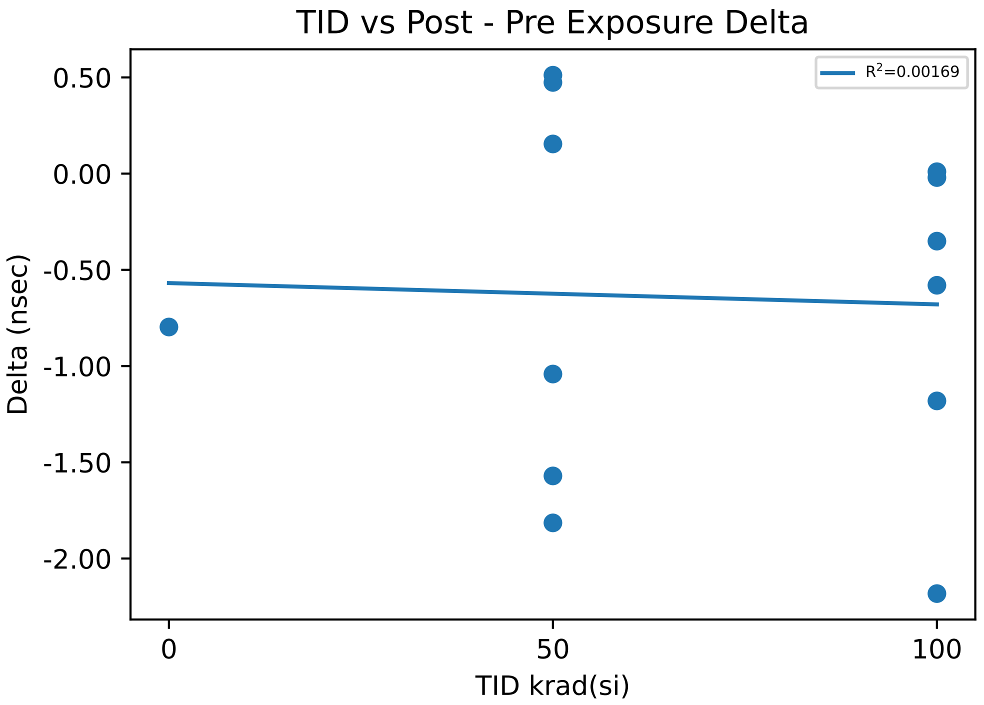
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.7029	5.0526	1.3497
60	50	Biased	5.2038	4.3783	-0.8255
61	50	Biased	3.2944	4.9657	1.6713
63	100	Biased	3.6323	5.5357	1.9034
64	100	Biased	5.3714	5.0949	-0.2765
65	100	Biased	3.8021	4.3823	0.5802
66	50	Unbiased	5.6103	4.3765	-1.2338
67	50	Unbiased	3.7961	5.2863	1.4902
68	50	Unbiased	5.4859	4.2107	-1.2752
69	100	Unbiased	4.5305	6.1061	1.5756
70	100	Unbiased	5.7709	5.1563	-0.6146
71	100	Unbiased	3.8894	5.6696	1.7802
72	0	Control	4.9079	3.7595	-1.1484

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9079	4.9079	4.9079		3.7595	3.7595	3.7595		-1.1484	-1.1484	-1.1484	
50	3.2944	4.5156	5.6103	1.0279	4.2107	4.7117	5.2863	0.44394	-1.2752	0.19612	1.6713	1.4446
100	3.6323	4.4994	5.7709	0.89311	4.3823	5.3242	6.1061	0.59048	-0.6146	0.82472	1.9034	1.094

Device Test: 96.2 DLH Dead Time Mid 500kHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

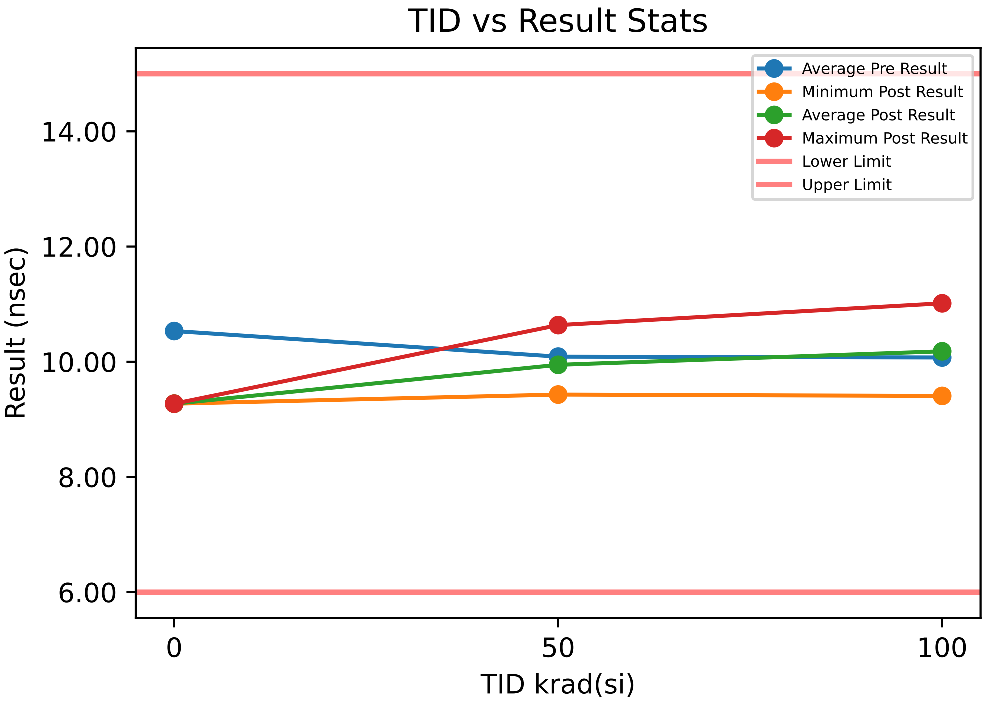
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

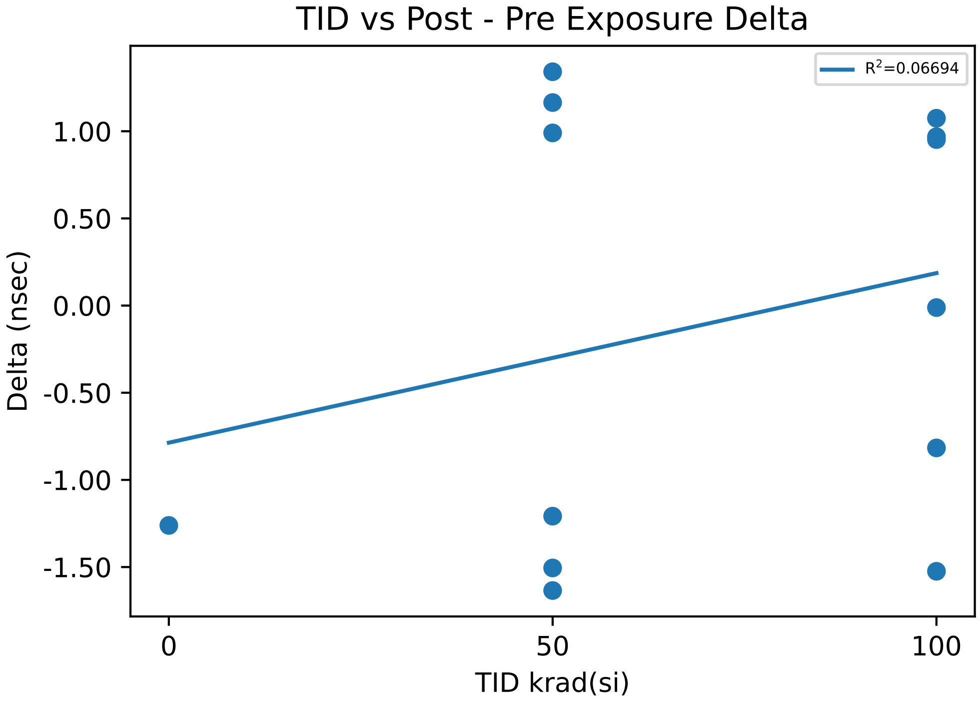
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	21.035	21.546	0.5115
60	50	Biased	21.614	19.799	-1.8148
61	50	Biased	21.174	21.328	0.1542
63	100	Biased	20.718	20.728	0.0099
64	100	Biased	21.275	20.695	-0.5801
65	100	Biased	21.234	20.053	-1.181
66	50	Unbiased	21.697	20.126	-1.5708
67	50	Unbiased	20.676	21.15	0.4738
68	50	Unbiased	21.778	20.736	-1.0414
69	100	Unbiased	21.322	20.971	-0.3508
70	100	Unbiased	21.561	19.379	-2.1823
71	100	Unbiased	20.179	20.159	-0.0204
72	0	Control	21.177	20.38	-0.797

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.177	21.177	21.177		20.38	20.38	20.38		-0.797	-0.797	-0.797	
50	20.676	21.329	21.778	0.437	19.799	20.781	21.546	0.69491	-1.8148	-0.54792	0.5115	1.0539
100	20.179	21.048	21.561	0.50758	19.379	20.331	20.971	0.58533	-2.1823	-0.71745	0.0099	0.8401

Device Test: 96.20 DHL Dead Time Small 500kHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

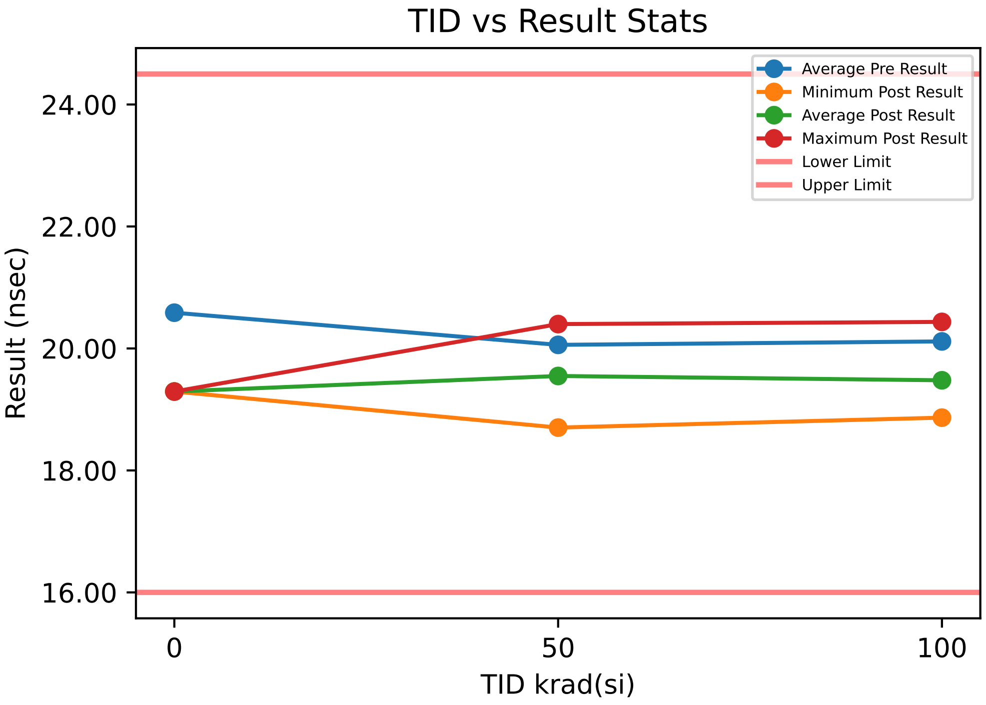
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

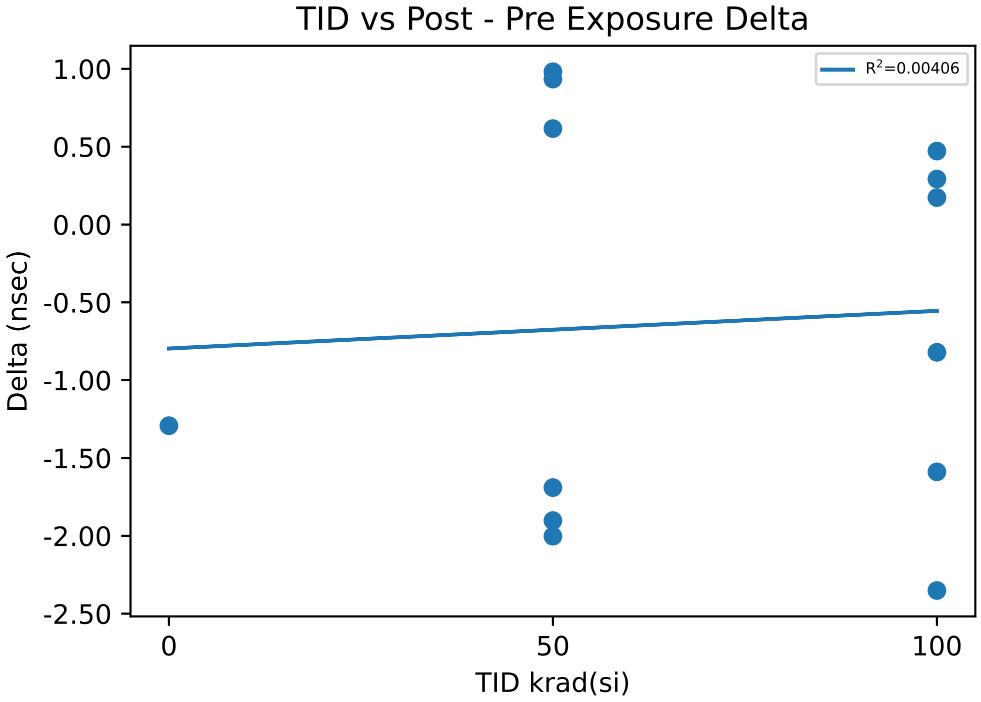
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	9.3432	10.334	0.9904
60	50	Biased	10.768	9.5605	-1.208
61	50	Biased	9.1154	10.28	1.1646
63	100	Biased	9.3918	10.466	1.0746
64	100	Biased	10.728	9.9114	-0.8165
65	100	Biased	9.4183	9.4068	-0.0115
66	50	Unbiased	10.935	9.4303	-1.5051
67	50	Unbiased	9.2949	10.636	1.3413
68	50	Unbiased	11.075	9.44	-1.6346
69	100	Unbiased	10.046	11.014	0.9687
70	100	Unbiased	11.322	9.7975	-1.5242
71	100	Unbiased	9.5395	10.492	0.9522
72	0	Control	10.533	9.272	-1.2612

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.533	10.533	10.533		9.272	9.272	9.272		-1.2612	-1.2612	-1.2612	
50	9.1154	10.089	11.075	0.92566	9.4303	9.9468	10.636	0.5308	-1.6346	-0.1419	1.3413	1.443
100	9.3918	10.074	11.322	0.79576	9.4068	10.181	11.014	0.5817	-1.5242	0.10722	1.0746	1.0882

Device Test: 96.21 DHL Dead Time Mid 500kHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

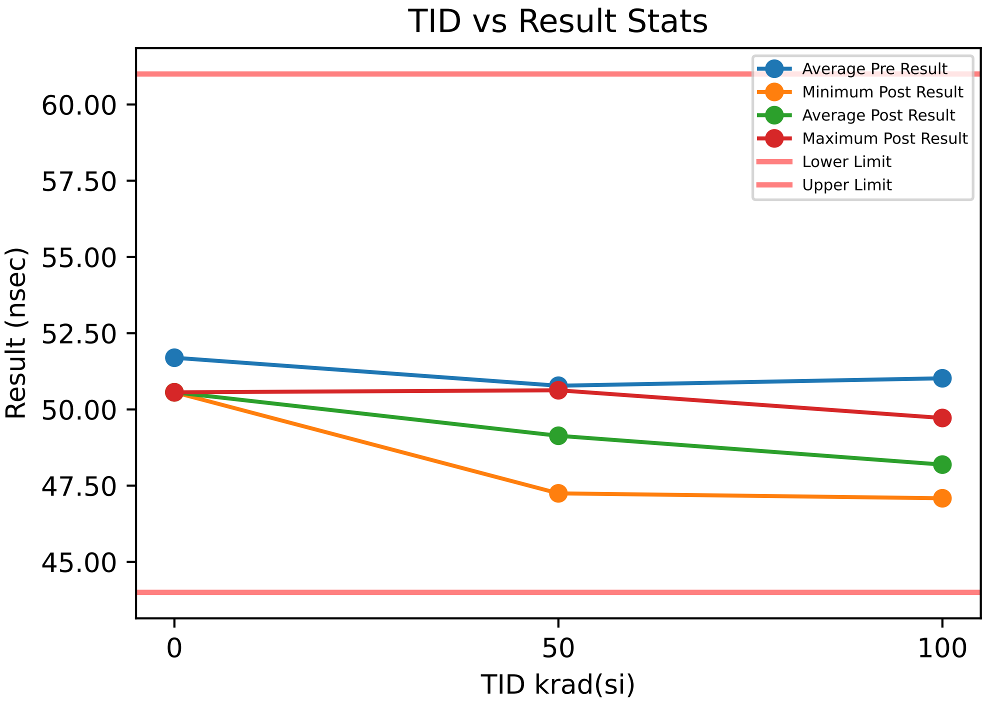
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

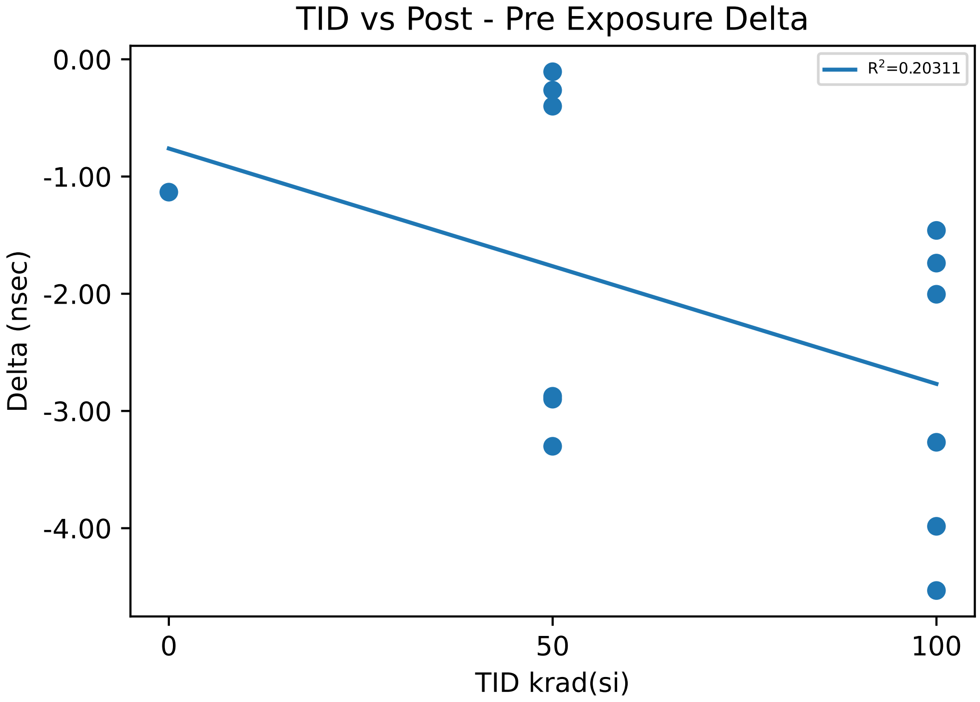
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	19.344	19.96	0.6164
60	50	Biased	20.675	18.985	-1.6901
61	50	Biased	19.18	20.161	0.9815
63	100	Biased	19.379	19.851	0.472
64	100	Biased	20.647	19.058	-1.5891
65	100	Biased	19.686	18.865	-0.821
66	50	Unbiased	20.605	18.702	-1.9021
67	50	Unbiased	19.465	20.399	0.9343
68	50	Unbiased	21.085	19.083	-2.0025
69	100	Unbiased	20.262	20.435	0.1731
70	100	Unbiased	21.228	18.877	-2.3513
71	100	Unbiased	19.489	19.782	0.2923
72	0	Control	20.586	19.294	-1.2924

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.586	20.586	20.586		19.294	19.294	19.294		-1.2924	-1.2924	-1.2924	
50	19.18	20.059	21.085	0.82077	18.702	19.548	20.399	0.70978	-2.0025	-0.51042	0.9815	1.4925
100	19.379	20.115	21.228	0.72951	18.865	19.478	20.435	0.64205	-2.3513	-0.63733	0.472	1.1514

Device Test: 96.22 DHL Dead Time Large 500kHz VIN_12V





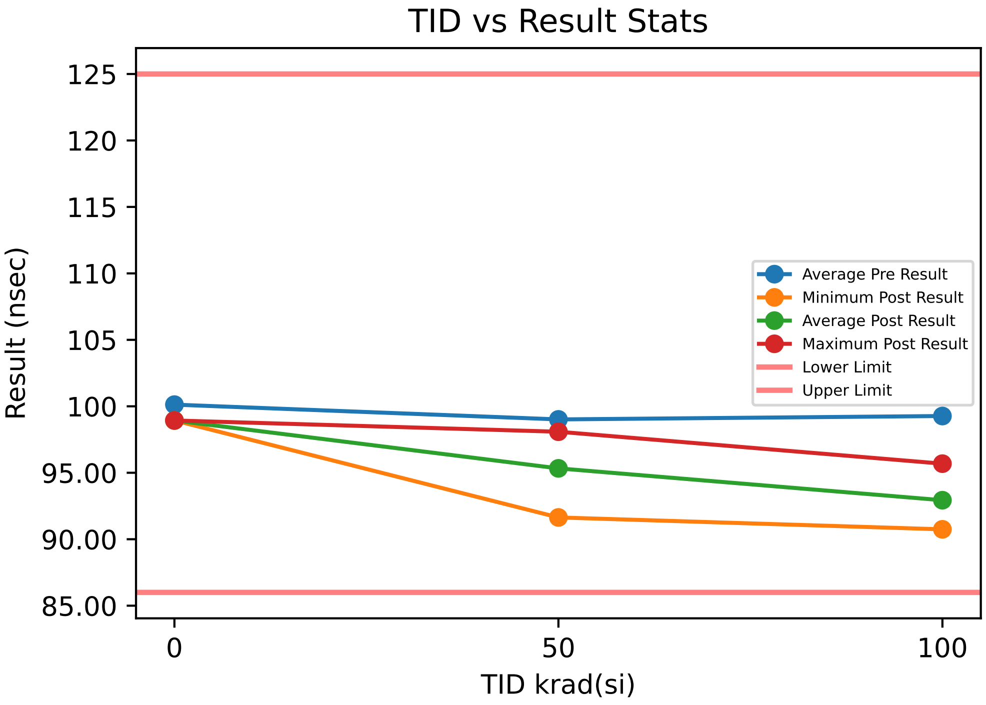
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	49.993	49.592	-0.4003
60	50	Biased	51.289	48.39	-2.8993
61	50	Biased	50.735	50.629	-0.1063
63	100	Biased	50.674	48.935	-1.7387
64	100	Biased	51.071	47.087	-3.9839
65	100	Biased	51.061	47.794	-3.2671
66	50	Unbiased	50.122	47.248	-2.8746
67	50	Unbiased	50.712	50.448	-0.2638
68	50	Unbiased	51.81	48.509	-3.3012
69	100	Unbiased	51.724	49.719	-2.0045
70	100	Unbiased	51.634	47.102	-4.5316
71	100	Unbiased	49.964	48.504	-1.4598
72	0	Control	51.695	50.562	-1.1333

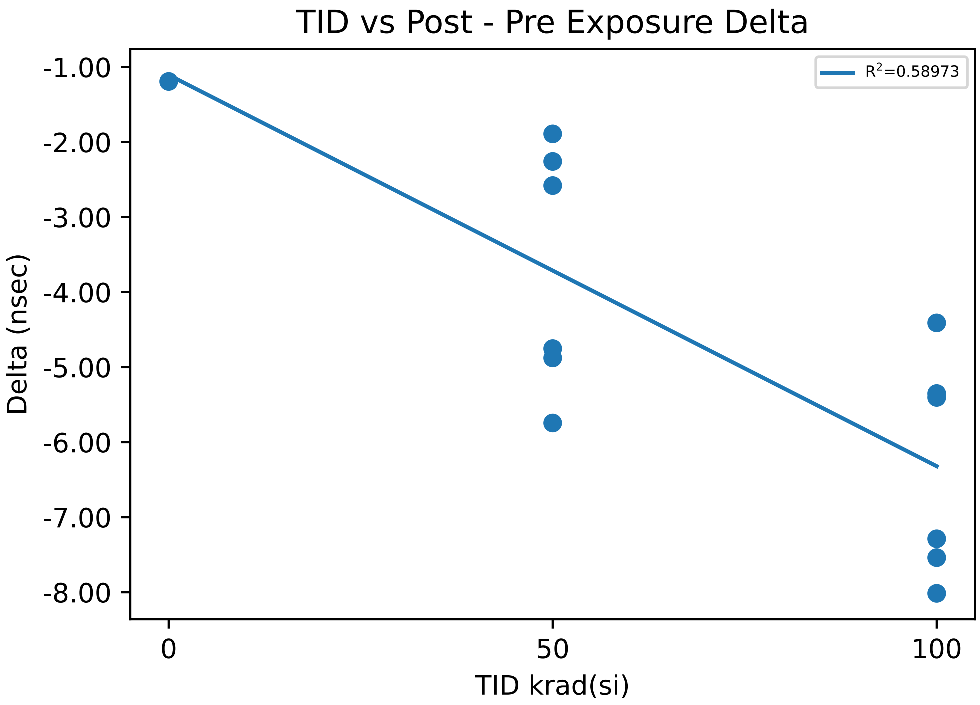
Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	51.695	51.695	51.695		50.562	50.562	50.562		-1.1333	-1.1333	-1.1333	
50	49.993	50.777	51.81	0.68995	47.248	49.136	50.629	1.3171	-3.3012	-1.6409	-0.1063	1.5266
100	49.964	51.021	51.724	0.64981	47.087	48.19	49.719	1.0535	-4.5316	-2.8309	-1.4598	1.2781

Device Test: 96.23 DHL Dead Time Max 500kHz VIN_12V



TID vs Result Stats



TID vs Post - Pre Exposure Delta

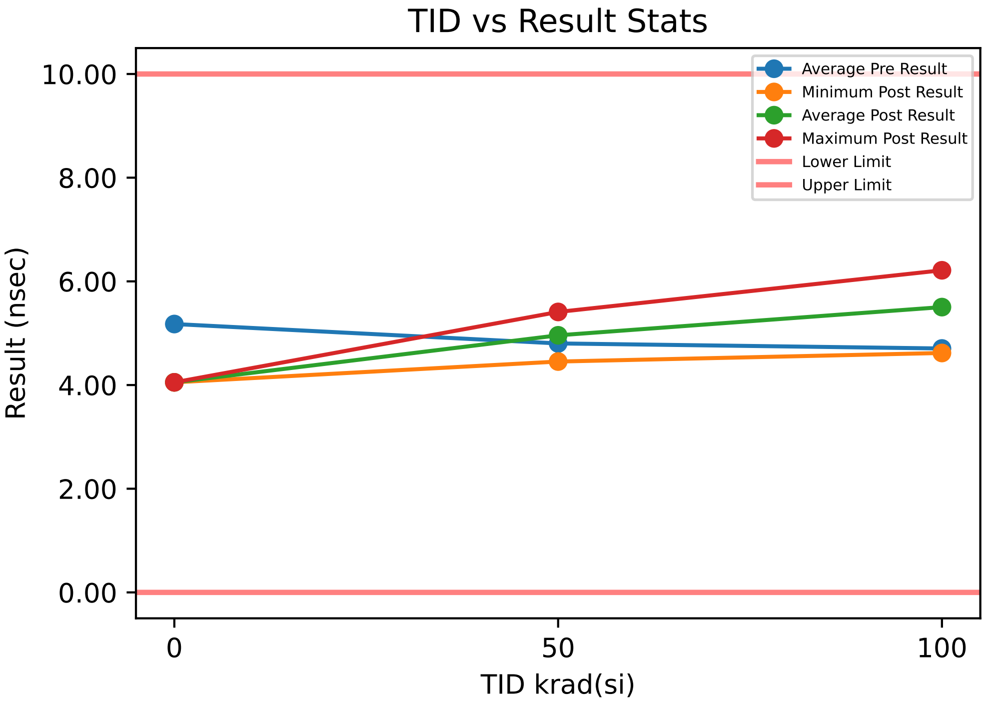
Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

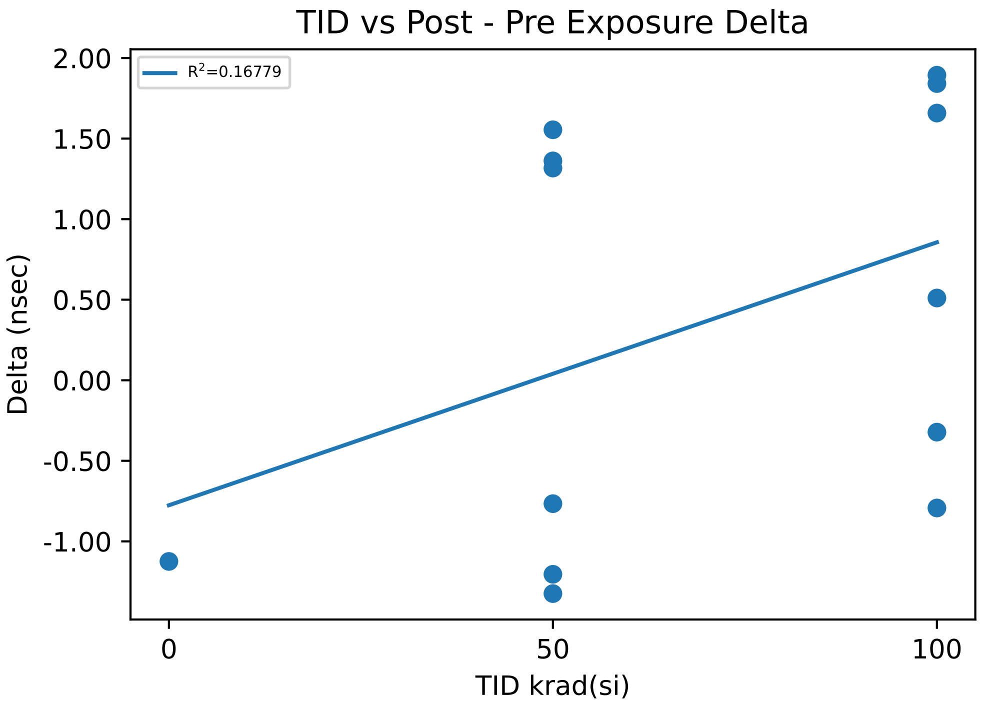
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	98.012	95.433	-2.5791
60	50	Biased	99.573	94.696	-4.8764
61	50	Biased	100.35	98.088	-2.2576
63	100	Biased	99.893	94.491	-5.4027
64	100	Biased	98.444	90.906	-7.538
65	100	Biased	99.957	92.671	-7.2867
66	50	Unbiased	96.391	91.639	-4.7521
67	50	Unbiased	99.463	97.574	-1.8899
68	50	Unbiased	100.3	94.559	-5.7433
69	100	Unbiased	101.04	95.685	-5.351
70	100	Unbiased	98.759	90.745	-8.0141
71	100	Unbiased	97.524	93.115	-4.4093
72	0	Control	100.13	98.935	-1.1914

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100.13	100.13	100.13		98.935	98.935	98.935		-1.1914	-1.1914	-1.1914	
50	96.391	99.014	100.35	1.538	91.639	95.331	98.088	2.3352	-5.7433	-3.6831	-1.8899	1.6296
100	97.524	99.269	101.04	1.2625	90.745	92.935	95.685	1.9492	-8.0141	-6.3336	-4.4093	1.4641

Device Test: 96.24 DHL Dead Time Min 1MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

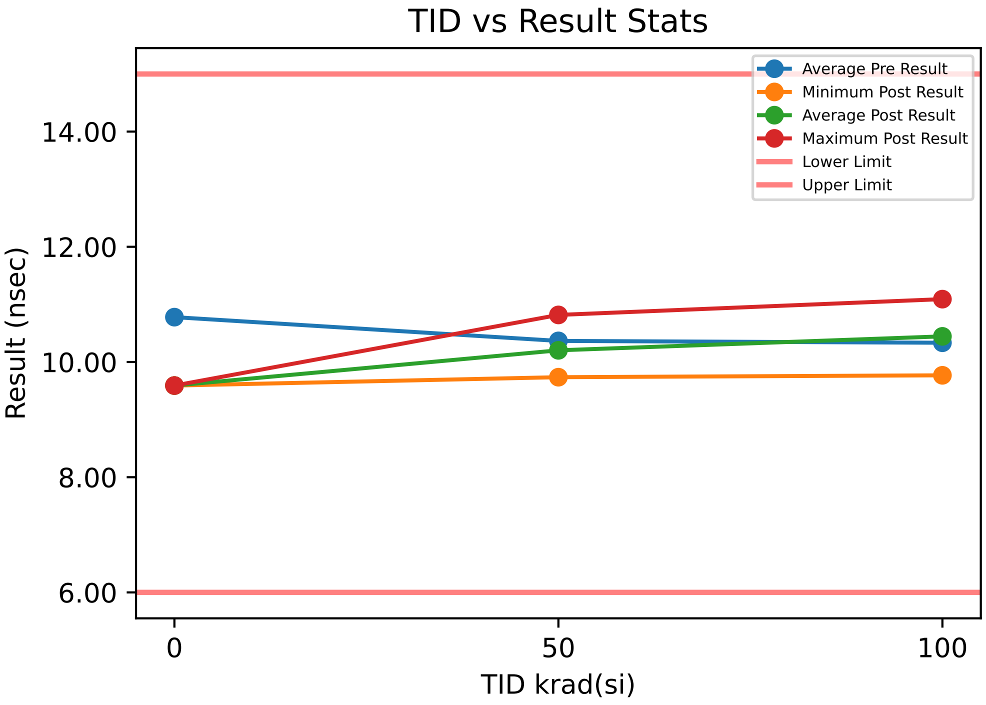
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

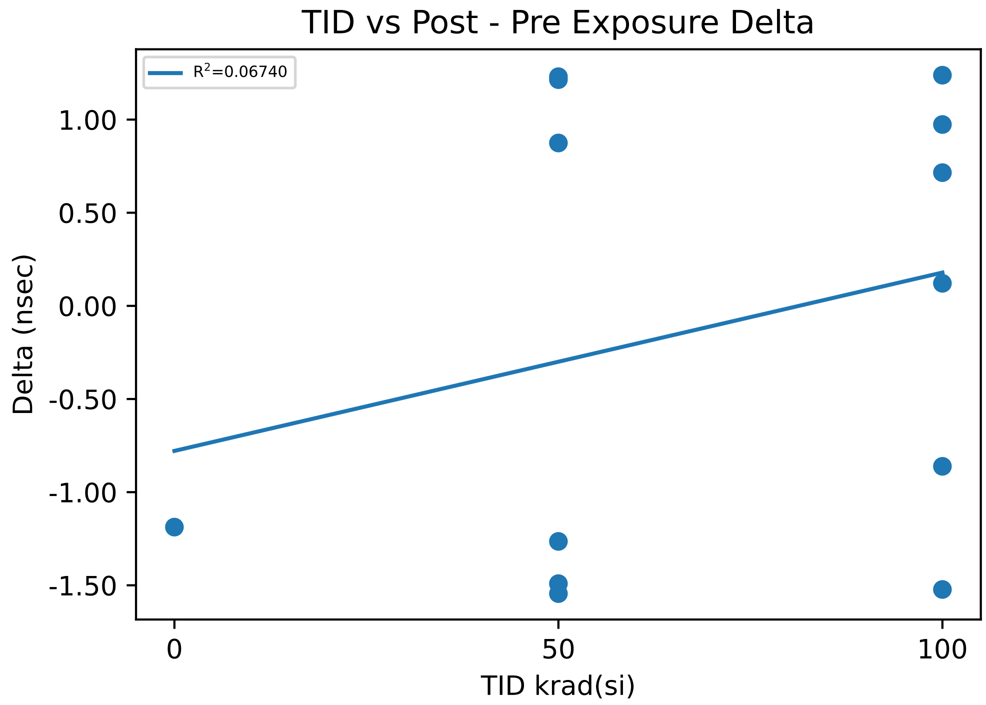
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.9964	5.358	1.3616
60	50	Biased	5.4965	4.7305	-0.766
61	50	Biased	3.5995	5.1542	1.5547
63	100	Biased	3.8284	5.7219	1.8935
64	100	Biased	5.5914	5.2694	-0.322
65	100	Biased	4.1079	4.6184	0.5105
66	50	Unbiased	5.8531	4.6486	-1.2045
67	50	Unbiased	4.0928	5.41	1.3172
68	50	Unbiased	5.7773	4.4531	-1.3242
69	100	Unbiased	4.5551	6.2136	1.6585
70	100	Unbiased	6.0144	5.2216	-0.7928
71	100	Unbiased	4.1339	5.9754	1.8415
72	0	Control	5.1768	4.0522	-1.1246

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.1768	5.1768	5.1768		4.0522	4.0522	4.0522		-1.1246	-1.1246	-1.1246	
50	3.5995	4.8026	5.8531	1.0135	4.4531	4.9591	5.41	0.4013	-1.3242	0.15647	1.5547	1.3893
100	3.8284	4.7052	6.0144	0.89149	4.6184	5.5034	6.2136	0.58177	-0.7928	0.7982	1.8935	1.1745

Device Test: 96.25 DHL Dead Time Small 1MHz VIN_12V





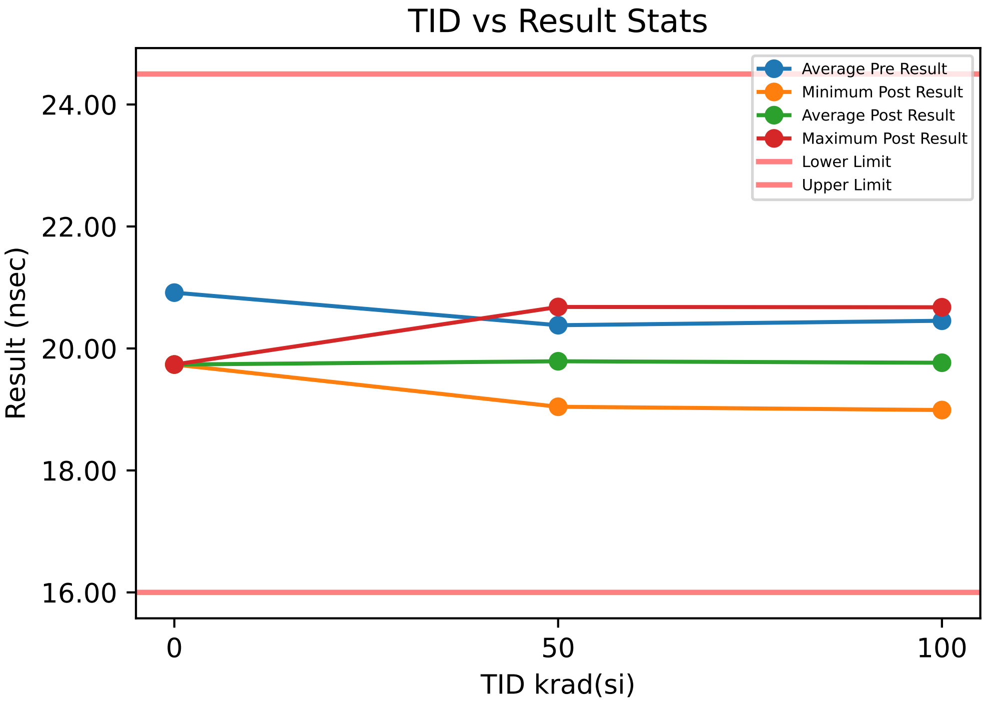
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

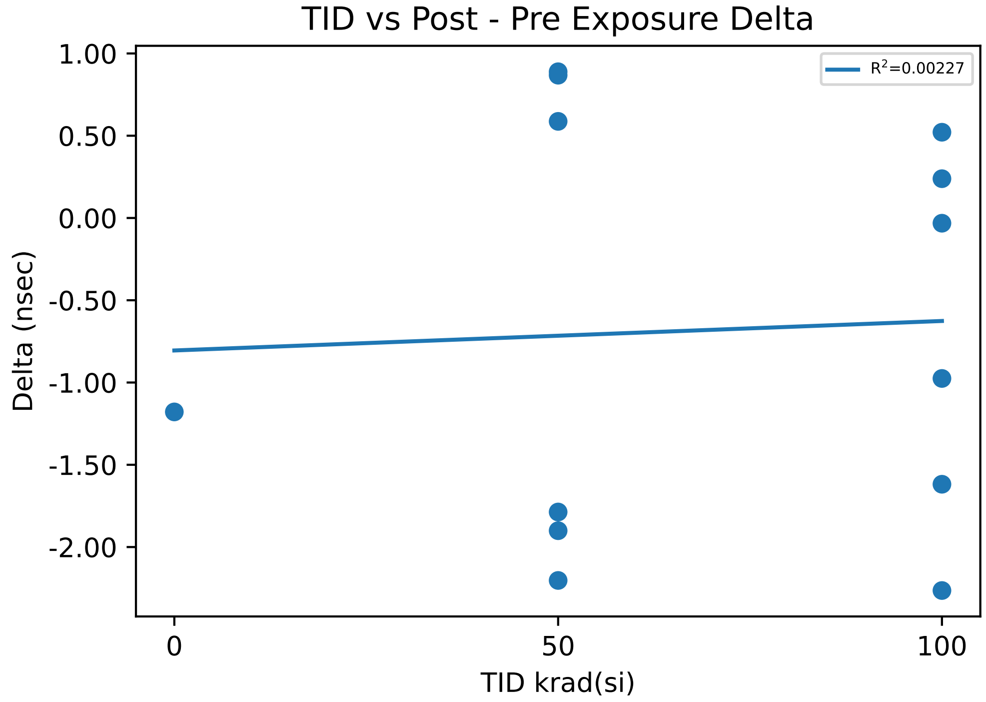
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	9.676	10.55	0.8745
60	50	Biased	11.055	9.7908	-1.2644
61	50	Biased	9.3194	10.55	1.2304
63	100	Biased	9.5382	10.777	1.2384
64	100	Biased	11.023	10.162	-0.8613
65	100	Biased	9.6477	9.7688	0.1211
66	50	Unbiased	11.227	9.7361	-1.4912
67	50	Unbiased	9.6027	10.817	1.2145
68	50	Unbiased	11.316	9.7718	-1.5446
69	100	Unbiased	10.376	11.091	0.7153
70	100	Unbiased	11.588	10.066	-1.5225
71	100	Unbiased	9.8321	10.806	0.9737
72	0	Control	10.779	9.591	-1.1876

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.779	10.779	10.779		9.591	9.591	9.591		-1.1876	-1.1876	-1.1876	
50	9.3194	10.366	11.316	0.92457	9.7361	10.203	10.817	0.48828	-1.5446	-0.16347	1.2304	1.4001
100	9.5382	10.334	11.588	0.82522	9.7688	10.445	11.091	0.51756	-1.5225	0.11078	1.2384	1.0949

Device Test: 96.26 DHL Dead Time Mid 1MHz VIN_12V





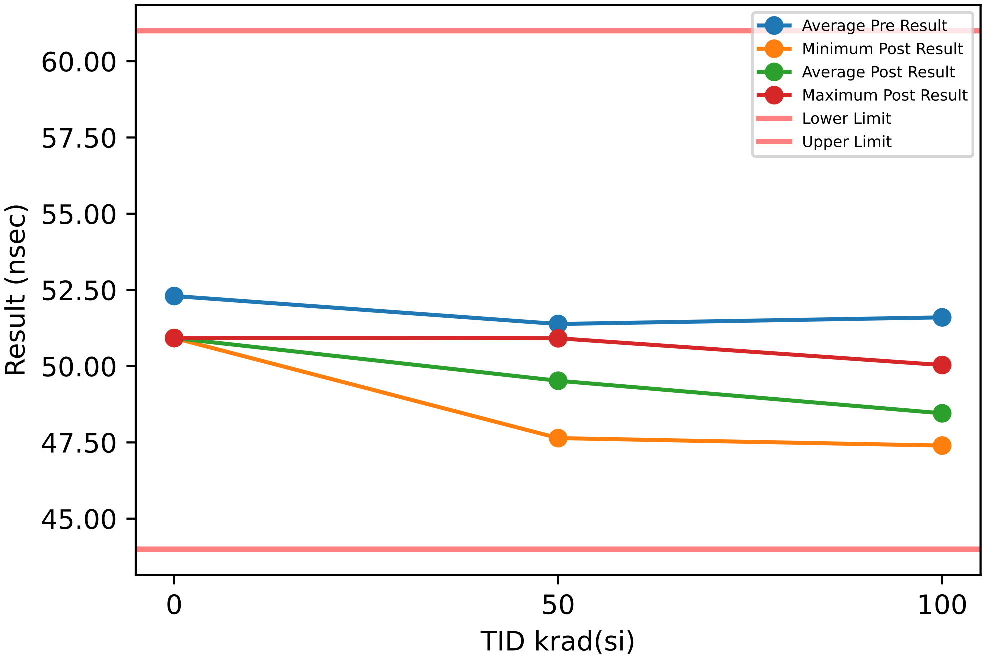
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

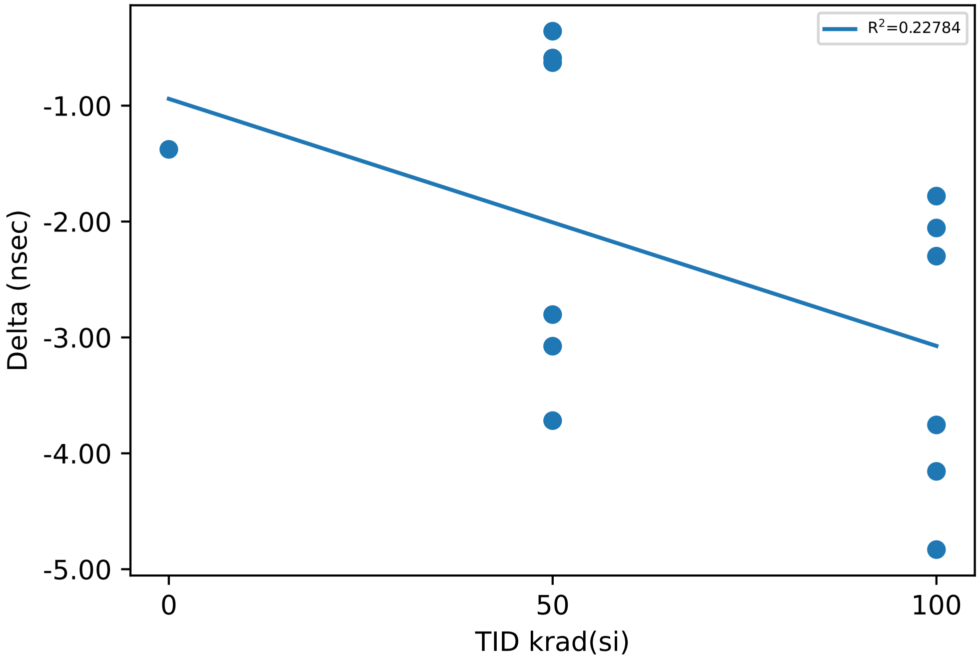
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	19.672	20.26	0.5872
60	50	Biased	20.972	19.185	-1.787
61	50	Biased	19.467	20.355	0.8888
63	100	Biased	19.694	20.216	0.5212
64	100	Biased	20.981	19.363	-1.6183
65	100	Biased	19.965	18.99	-0.9753
66	50	Unbiased	20.944	19.044	-1.9006
67	50	Unbiased	19.812	20.68	0.8679
68	50	Unbiased	21.417	19.214	-2.203
69	100	Unbiased	20.707	20.675	-0.0318
70	100	Unbiased	21.55	19.285	-2.2642
71	100	Unbiased	19.826	20.065	0.2388
72	0	Control	20.915	19.736	-1.1787

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.915	20.915	20.915		19.736	19.736	19.736		-1.1787	-1.1787	-1.1787	
50	19.467	20.381	21.417	0.82476	19.044	19.79	20.68	0.71938	-2.203	-0.59112	0.8888	1.5133
100	19.694	20.454	21.55	0.74193	18.99	19.766	20.675	0.65016	-2.2642	-0.68827	0.5212	1.1121

Device Test: 96.27 DHL Dead Time Large 1MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

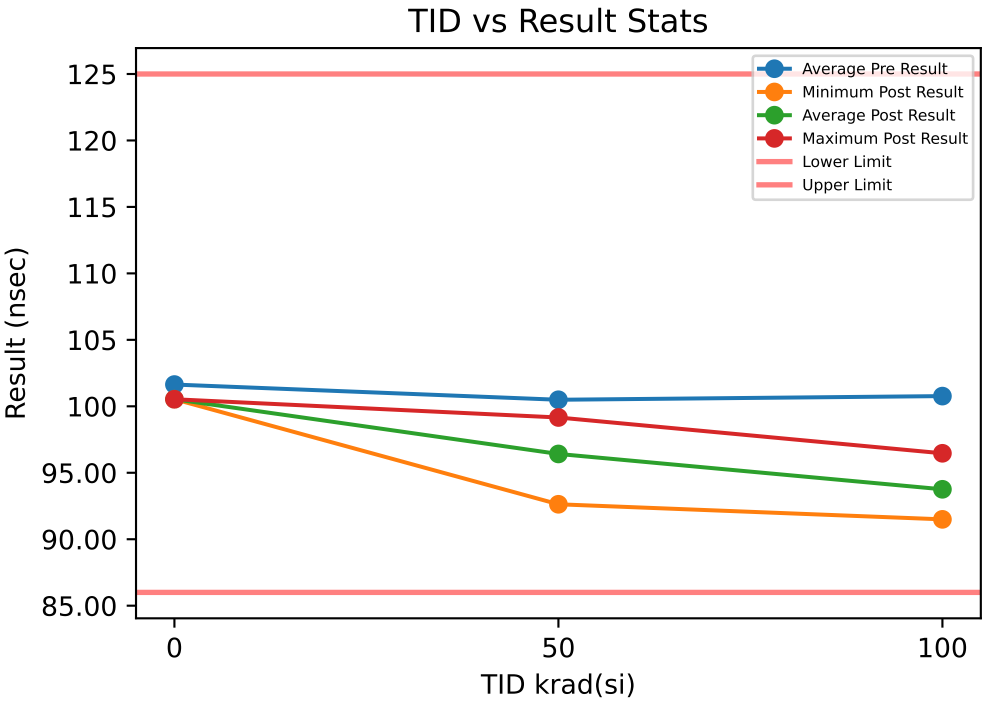
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

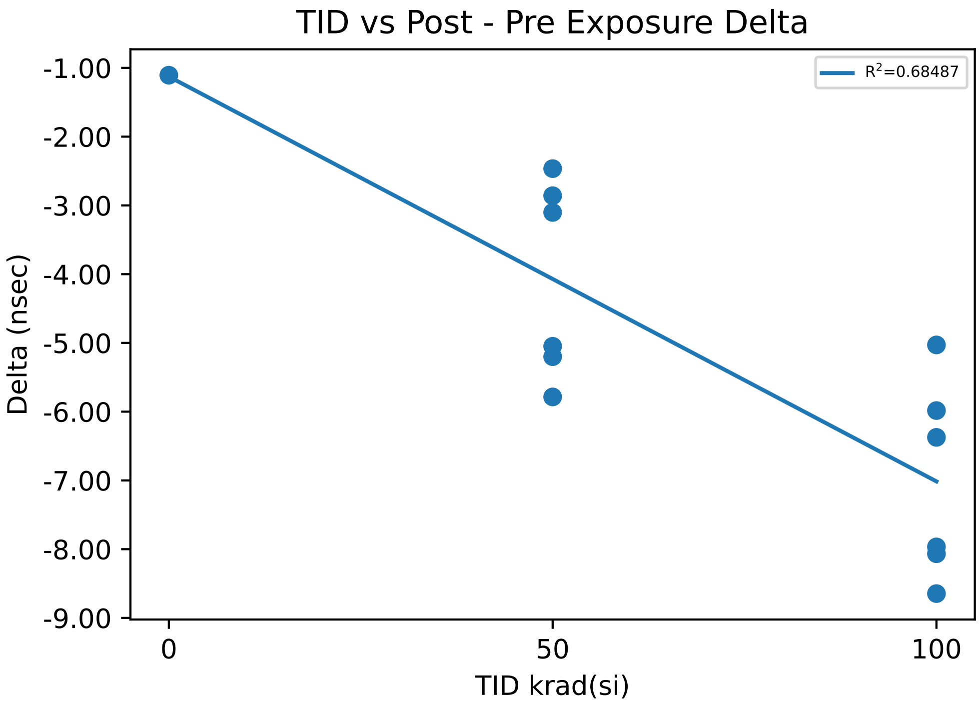
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	50.572	49.944	-0.6288
60	50	Biased	51.821	49.018	-2.8029
61	50	Biased	51.403	50.814	-0.5886
63	100	Biased	51.227	49.171	-2.0556
64	100	Biased	51.568	47.413	-4.1558
65	100	Biased	51.662	47.907	-3.755
66	50	Unbiased	50.717	47.642	-3.0756
67	50	Unbiased	51.273	50.915	-0.3575
68	50	Unbiased	52.518	48.8	-3.718
69	100	Unbiased	52.337	50.038	-2.2988
70	100	Unbiased	52.227	47.396	-4.8308
71	100	Unbiased	50.586	48.806	-1.7805
72	0	Control	52.3	50.923	-1.3772

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.3	52.3	52.3		50.923	50.923	50.923		-1.3772	-1.3772	-1.3772	
50	50.572	51.384	52.518	0.72016	47.642	49.522	50.915	1.2728	-3.718	-1.8619	-0.3575	1.4972
100	50.586	51.601	52.337	0.64931	47.396	48.455	50.038	1.063	-4.8308	-3.1461	-1.7805	1.2649

Device Test: 96.28 DHL Dead Time Max 1MHz VIN_12V





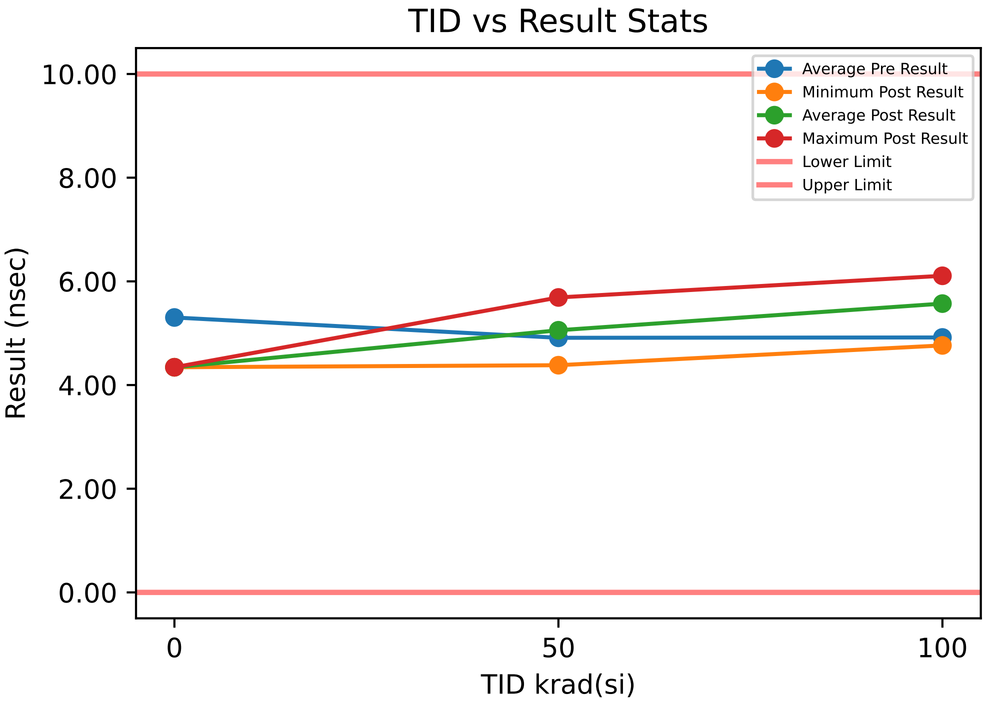
Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

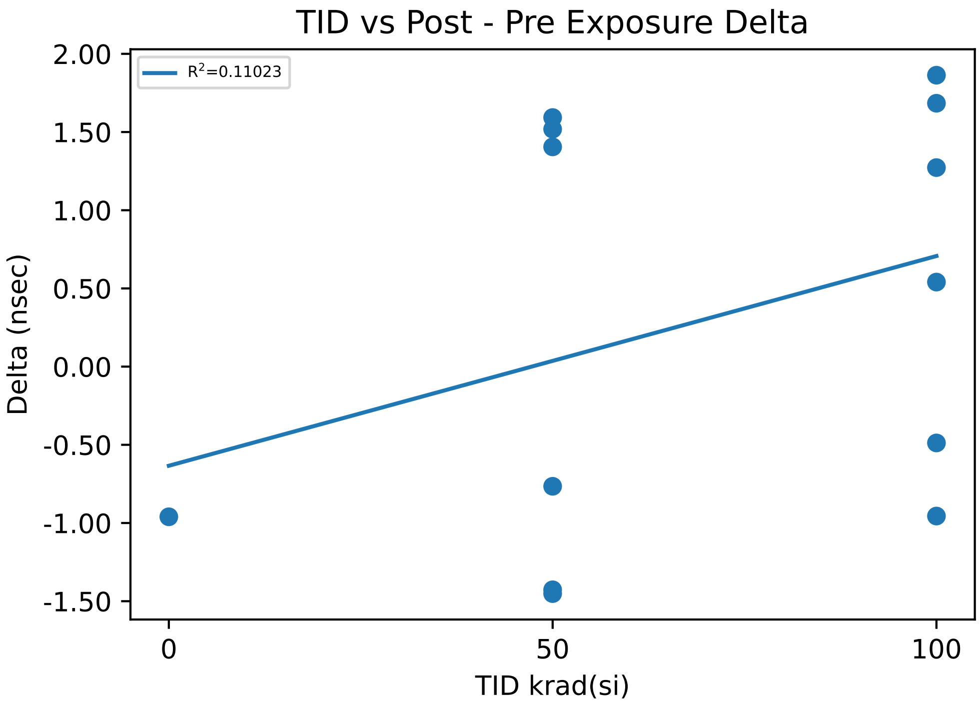
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	99.535	96.433	-3.1025
60	50	Biased	101.04	95.841	-5.2002
61	50	Biased	102.02	99.159	-2.8589
63	100	Biased	101.57	95.196	-6.3736
64	100	Biased	99.908	91.841	-8.0665
65	100	Biased	101.55	93.584	-7.9666
66	50	Unbiased	97.679	92.63	-5.049
67	50	Unbiased	100.97	98.51	-2.4652
68	50	Unbiased	101.71	95.922	-5.7855
69	100	Unbiased	102.45	96.466	-5.9839
70	100	Unbiased	100.14	91.496	-8.6461
71	100	Unbiased	98.988	93.959	-5.0291
72	0	Control	101.64	100.53	-1.1062

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	101.64	101.64	101.64		100.53	100.53	100.53		-1.1062	-1.1062	-1.1062	
50	97.679	100.49	102.02	1.623	92.63	96.416	99.159	2.3159	-5.7855	-4.0769	-2.4652	1.4252
100	98.988	100.77	102.45	1.295	91.496	93.757	96.466	1.9112	-8.6461	-7.011	-5.0291	1.4206

Device Test: 96.29 DHL Dead Time Min 2MHz VIN_12V





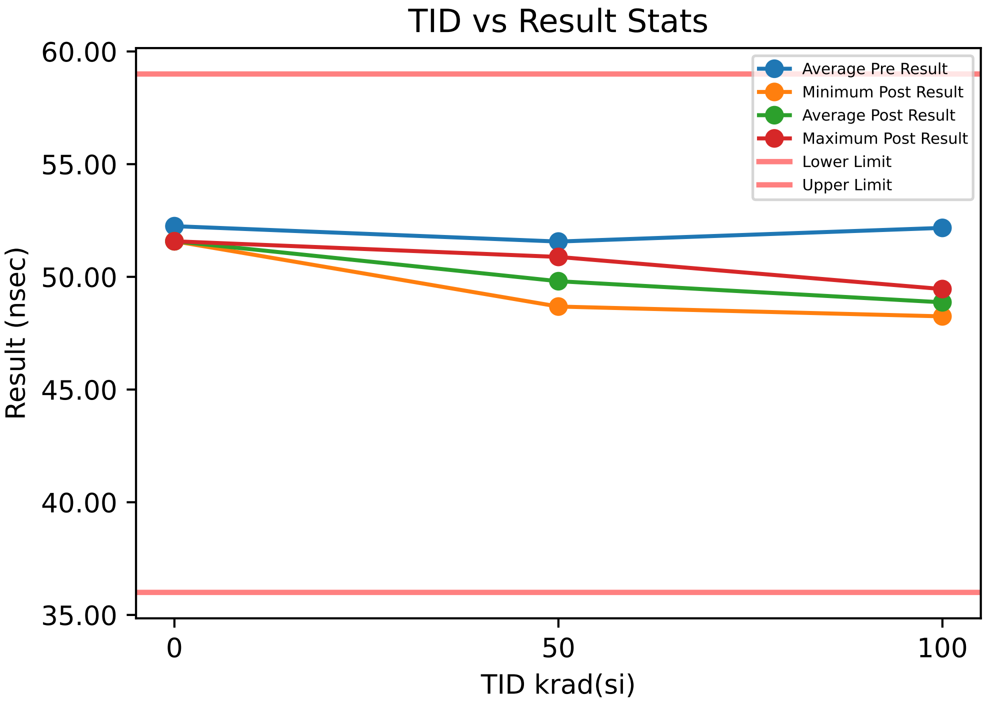
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

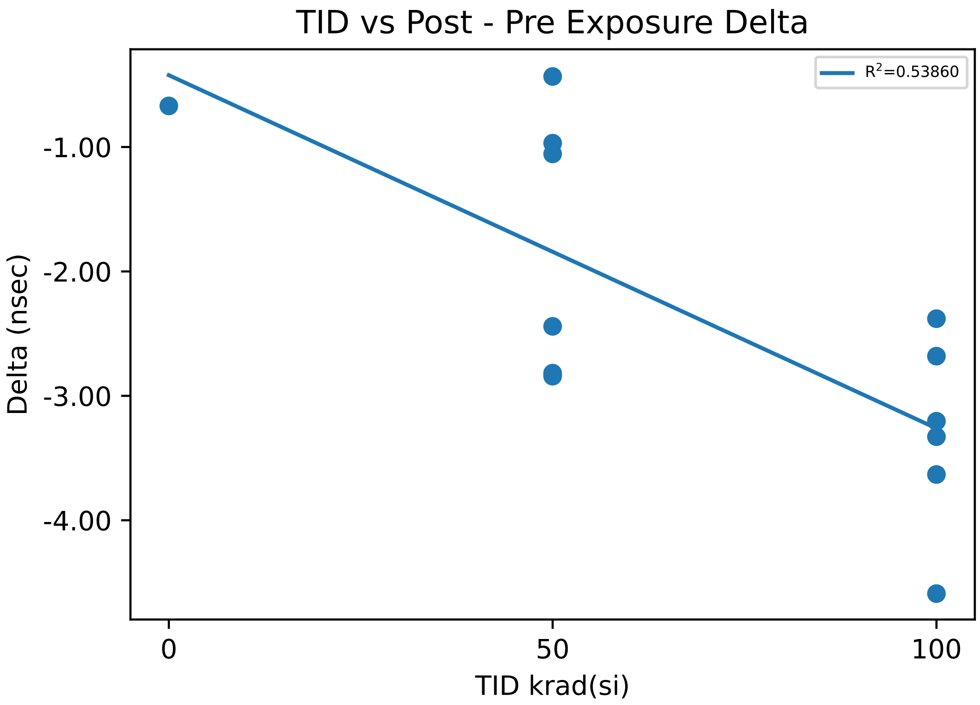
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.0965	5.5016	1.4051
60	50	Biased	5.638	4.8728	-0.7652
61	50	Biased	3.8182	5.3366	1.5184
63	100	Biased	4.0634	5.9268	1.8634
64	100	Biased	5.7713	5.2832	-0.4881
65	100	Biased	4.2238	4.7644	0.5406
66	50	Unbiased	5.983	4.556	-1.427
67	50	Unbiased	4.0968	5.6895	1.5927
68	50	Unbiased	5.8339	4.3825	-1.4514
69	100	Unbiased	4.8062	6.0788	1.2726
70	100	Unbiased	6.22	5.2645	-0.9555
71	100	Unbiased	4.4233	6.1073	1.684
72	0	Control	5.3032	4.343	-0.9602

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.3032	5.3032	5.3032		4.343	4.343	4.343		-0.9602	-0.9602	-0.9602	
50	3.8182	4.9111	5.983	1.005	4.3825	5.0565	5.6895	0.53212	-1.4514	0.14543	1.5927	1.5112
100	4.0634	4.918	6.22	0.88236	4.7644	5.5708	6.1073	0.54762	-0.9555	0.65283	1.8634	1.1674

Device Test: 96.3 DLH Dead Time Large 500kHz VIN_12V





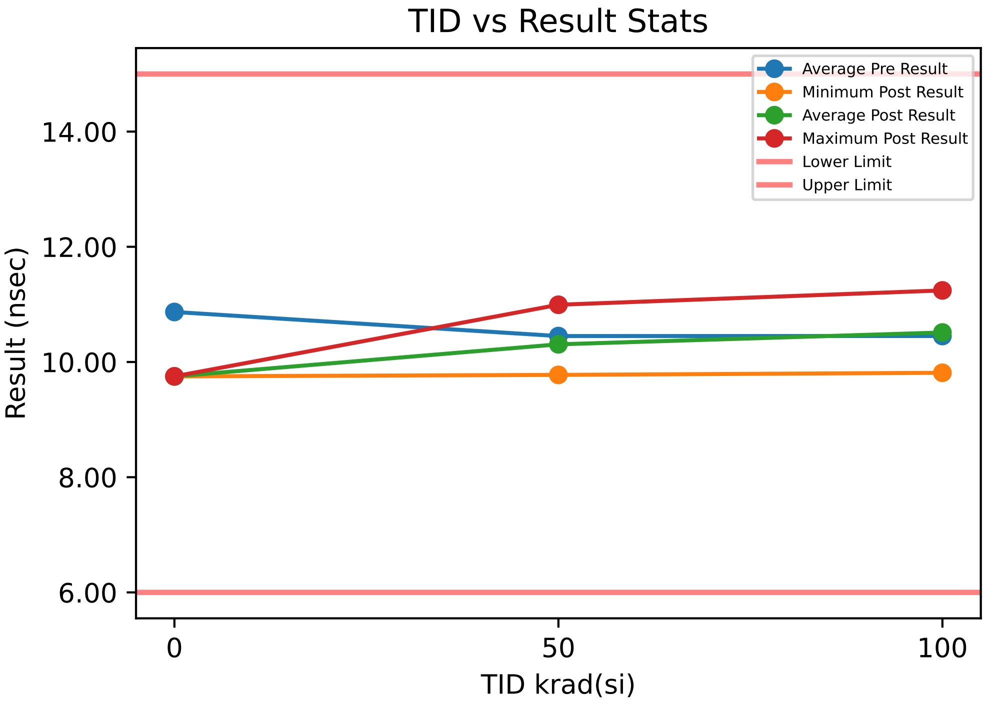
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

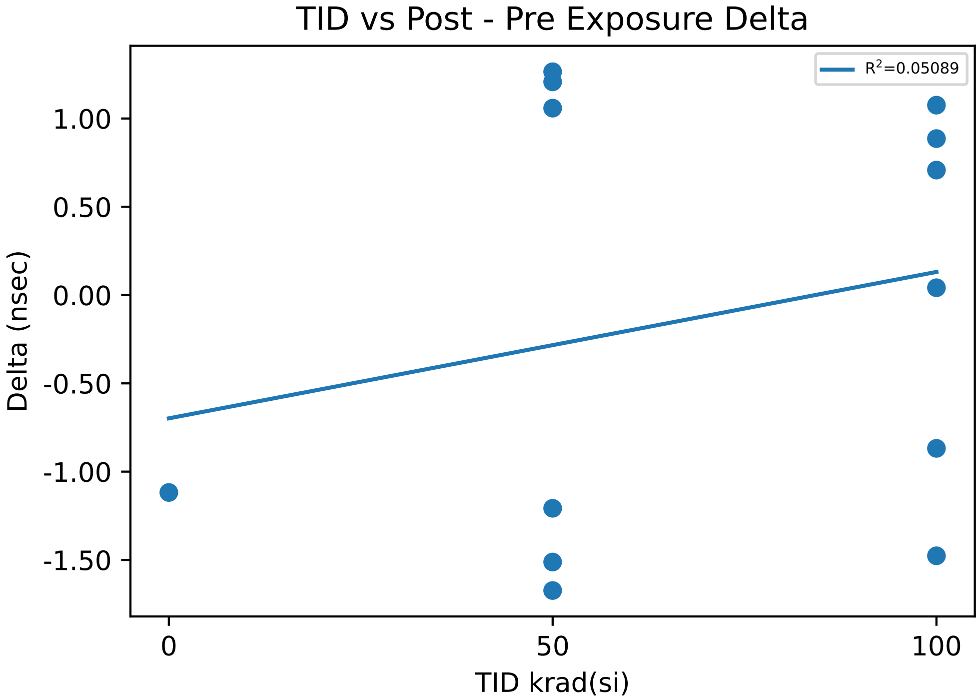
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	51.317	50.884	-0.4331
60	50	Biased	51.5	48.682	-2.8176
61	50	Biased	51.234	50.179	-1.0555
63	100	Biased	50.871	48.491	-2.3798
64	100	Biased	51.914	48.586	-3.3283
65	100	Biased	52.846	49.214	-3.6322
66	50	Unbiased	52.048	49.206	-2.8419
67	50	Unbiased	51.249	50.28	-0.9691
68	50	Unbiased	52.049	49.608	-2.4415
69	100	Unbiased	52.662	49.458	-3.2042
70	100	Unbiased	52.836	48.247	-4.5895
71	100	Unbiased	51.907	49.226	-2.6809
72	0	Control	52.249	51.579	-0.6696

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.249	52.249	52.249		51.579	51.579	51.579		-0.6696	-0.6696	-0.6696	
50	51.234	51.566	52.049	0.38543	48.682	49.807	50.884	0.79844	-2.8419	-1.7598	-0.4331	1.0617
100	50.871	52.173	52.846	0.77013	48.247	48.87	49.458	0.49072	-4.5895	-3.3025	-2.3798	0.77629

Device Test: 96.30 DHL Dead Time Small 2MHz VIN_12V





Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

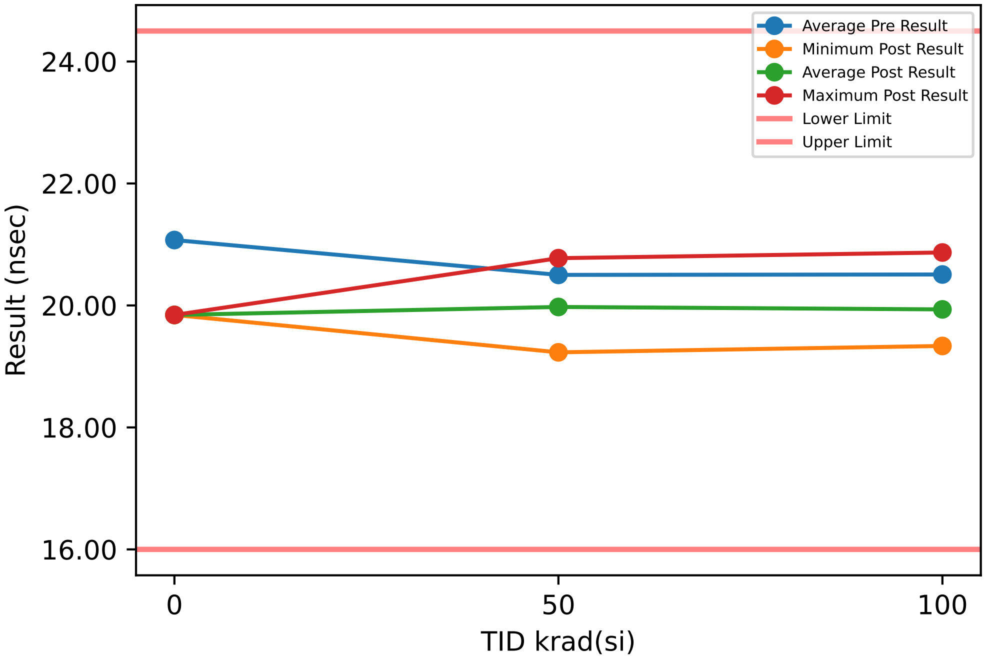
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	9.6874	10.746	1.0586
60	50	Biased	11.104	9.8964	-1.2075
61	50	Biased	9.4344	10.642	1.2076
63	100	Biased	9.711	10.787	1.0756
64	100	Biased	11.139	10.271	-0.8681
65	100	Biased	9.771	9.8126	0.0416
66	50	Unbiased	11.298	9.7863	-1.5119
67	50	Unbiased	9.7288	10.994	1.2648
68	50	Unbiased	11.449	9.7761	-1.6732
69	100	Unbiased	10.535	11.243	0.7079
70	100	Unbiased	11.681	10.204	-1.4766
71	100	Unbiased	9.869	10.755	0.8863
72	0	Control	10.868	9.7505	-1.118

Test Statistics (nsec)

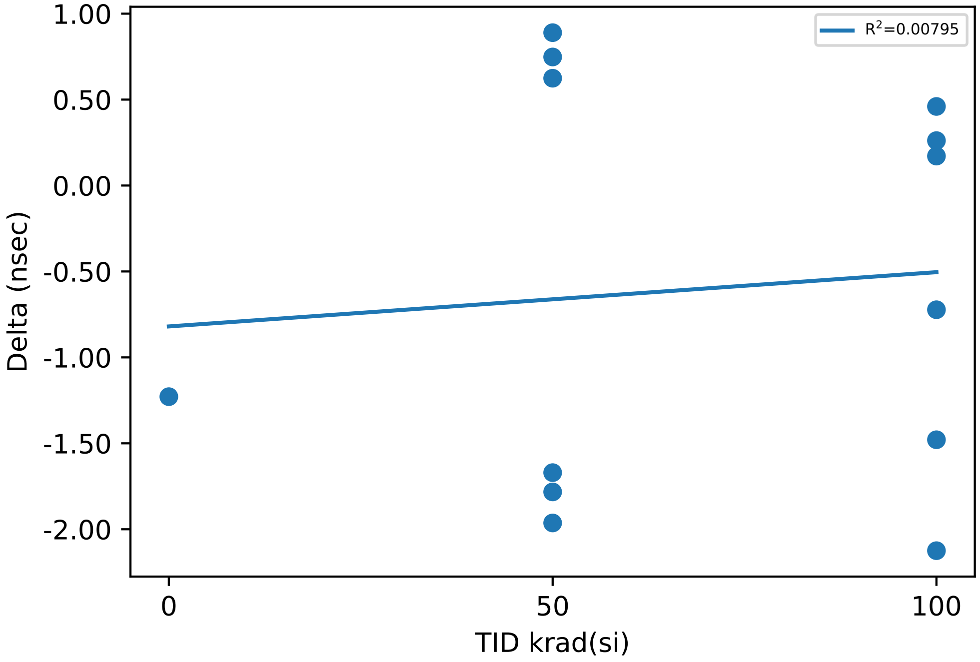
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.868	10.868	10.868		9.7505	9.7505	9.7505		-1.118	-1.118	-1.118	
50	9.4344	10.45	11.449	0.92507	9.7761	10.307	10.994	0.54735	-1.6732	-0.1436	1.2648	1.4559
100	9.711	10.451	11.681	0.81759	9.8126	10.512	11.243	0.51193	-1.4766	0.061117	1.0756	1.0351

Device Test: 96.31 DHL Dead Time Mid 2MHz VIN_12V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



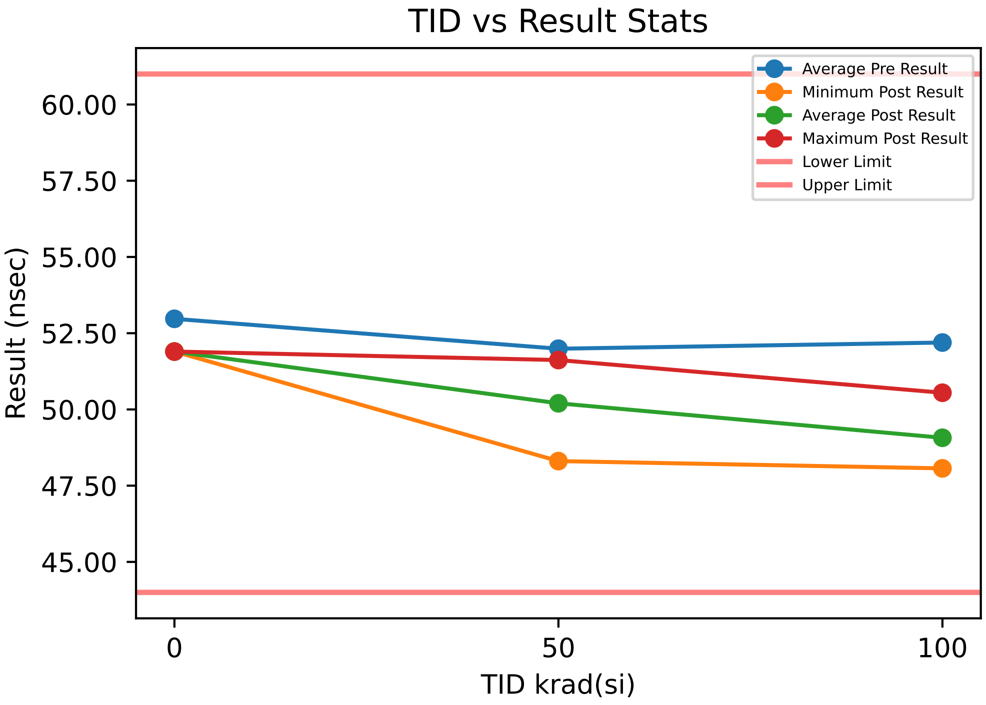
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

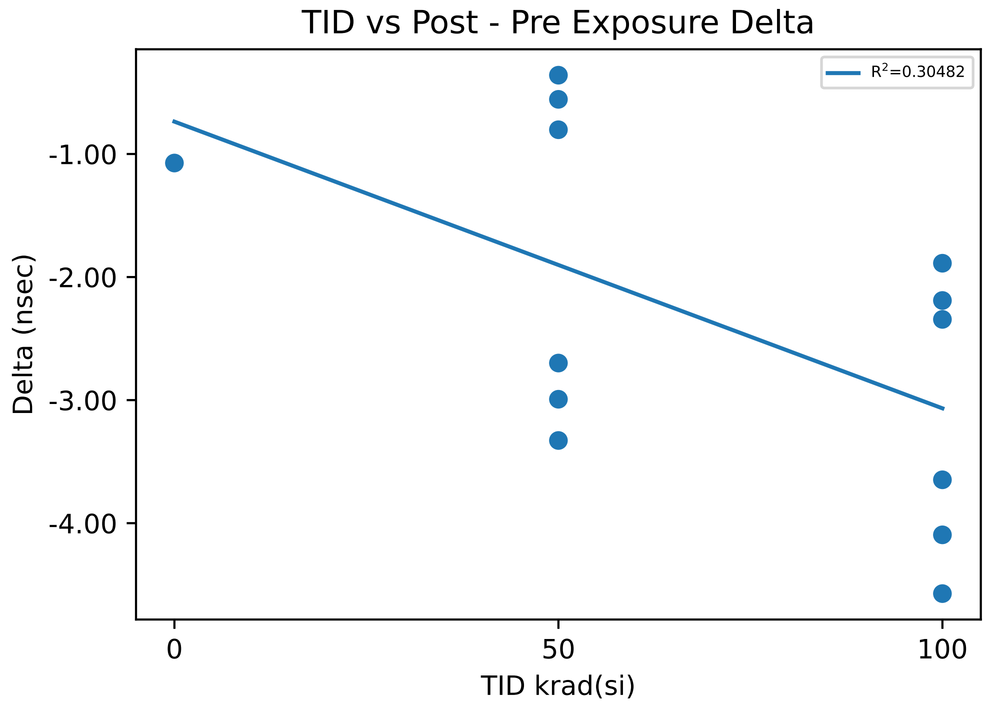
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	19.674	20.299	0.6244
60	50	Biased	21.104	19.434	-1.6706
61	50	Biased	19.662	20.551	0.8894
63	100	Biased	19.762	20.222	0.4601
64	100	Biased	21.06	19.581	-1.4792
65	100	Biased	20.058	19.336	-0.7227
66	50	Unbiased	21.014	19.231	-1.7828
67	50	Unbiased	20.027	20.775	0.748
68	50	Unbiased	21.524	19.561	-1.9634
69	100	Unbiased	20.607	20.868	0.2614
70	100	Unbiased	21.671	19.547	-2.1247
71	100	Unbiased	19.888	20.059	0.1713
72	0	Control	21.073	19.844	-1.2285

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.073	21.073	21.073		19.844	19.844	19.844		-1.2285	-1.2285	-1.2285	
50	19.662	20.501	21.524	0.81088	19.231	19.975	20.775	0.64717	-1.9634	-0.52583	0.8894	1.4075
100	19.762	20.508	21.671	0.74987	19.336	19.935	20.868	0.56639	-2.1247	-0.5723	0.4601	1.0554

Device Test: 96.32 DHL Dead Time Large 2MHz VIN_12V





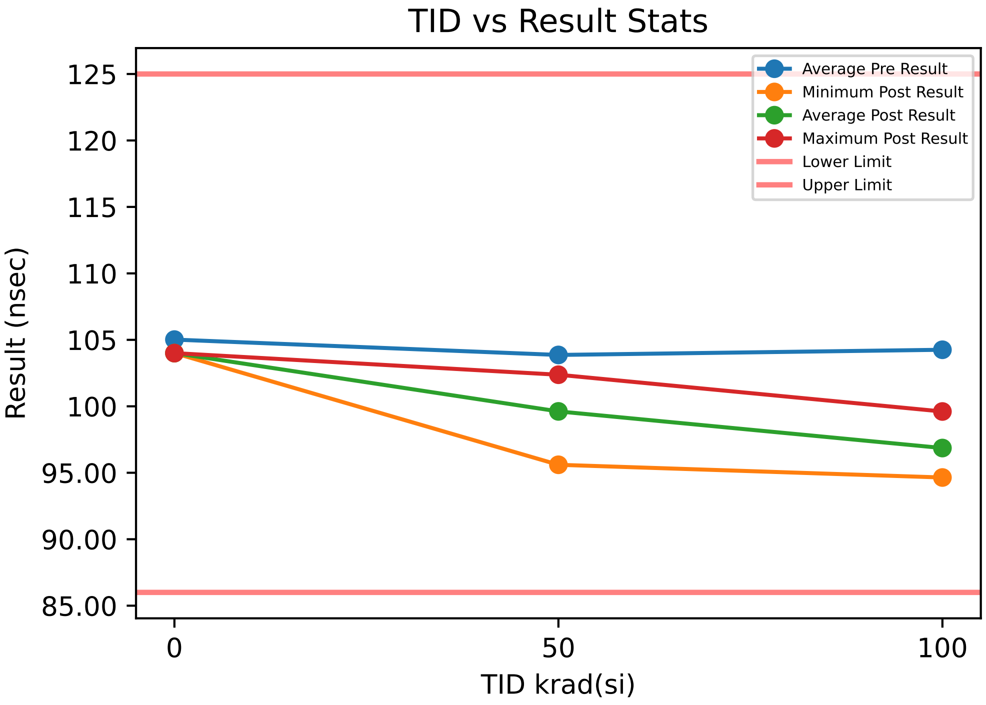
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

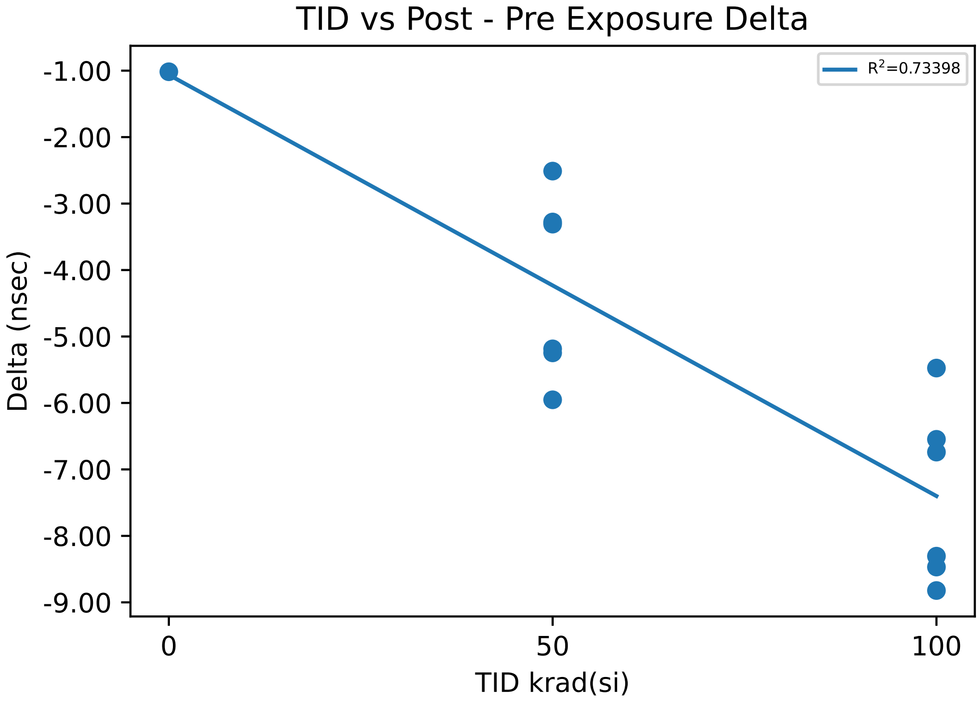
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	51.277	50.474	-0.8029
60	50	Biased	52.389	49.69	-2.6988
61	50	Biased	51.979	51.62	-0.3597
63	100	Biased	51.923	49.733	-2.1904
64	100	Biased	52.162	48.067	-4.0948
65	100	Biased	52.305	48.657	-3.6475
66	50	Unbiased	51.299	48.306	-2.9929
67	50	Unbiased	51.989	51.433	-0.5559
68	50	Unbiased	53.014	49.686	-3.3281
69	100	Unbiased	52.892	50.547	-2.3441
70	100	Unbiased	52.709	48.137	-4.5723
71	100	Unbiased	51.171	49.284	-1.8877
72	0	Control	52.971	51.898	-1.0734

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.971	52.971	52.971		51.898	51.898	51.898		-1.0734	-1.0734	-1.0734	
50	51.277	51.991	53.014	0.6622	48.306	50.201	51.62	1.2429	-3.3281	-1.7897	-0.3597	1.3551
100	51.171	52.194	52.892	0.61385	48.067	49.071	50.547	0.97101	-4.5723	-3.1228	-1.8877	1.1245

Device Test: 96.33 DHL Dead Time Max 2MHz VIN_12V





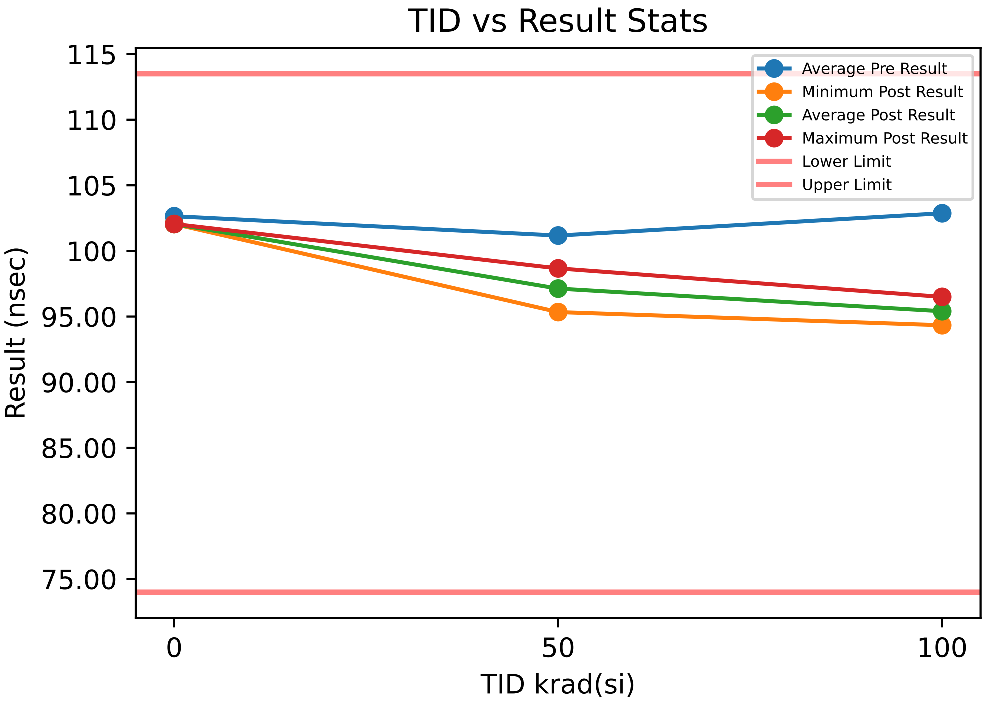
Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

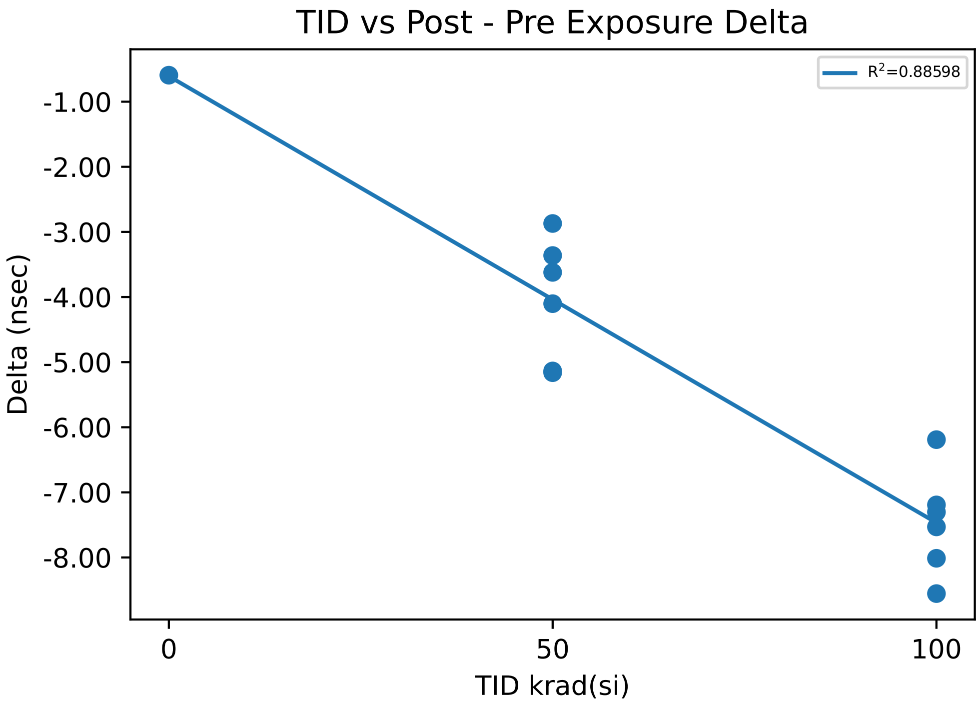
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	102.92	99.615	-3.3093
60	50	Biased	104.4	99.158	-5.2463
61	50	Biased	105.65	102.38	-3.2773
63	100	Biased	105.16	98.417	-6.7394
64	100	Biased	103.2	94.736	-8.4689
65	100	Biased	105.08	96.772	-8.3052
66	50	Unbiased	100.79	95.601	-5.186
67	50	Unbiased	104.33	101.82	-2.5114
68	50	Unbiased	105.08	99.131	-5.9524
69	100	Unbiased	106.16	99.61	-6.5472
70	100	Unbiased	103.47	94.644	-8.8221
71	100	Unbiased	102.46	96.987	-5.4749
72	0	Control	105.02	104	-1.0165

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	105.02	105.02	105.02		104	104	104		-1.0165	-1.0165	-1.0165	
50	100.79	103.86	105.65	1.7634	95.601	99.617	102.38	2.41	-5.9524	-4.2471	-2.5114	1.3871
100	102.46	104.25	106.16	1.4176	94.644	96.861	99.61	1.9714	-8.8221	-7.3929	-5.4749	1.3307

Device Test: 96.4 DLH Dead Time Max 500kHz VIN_12V





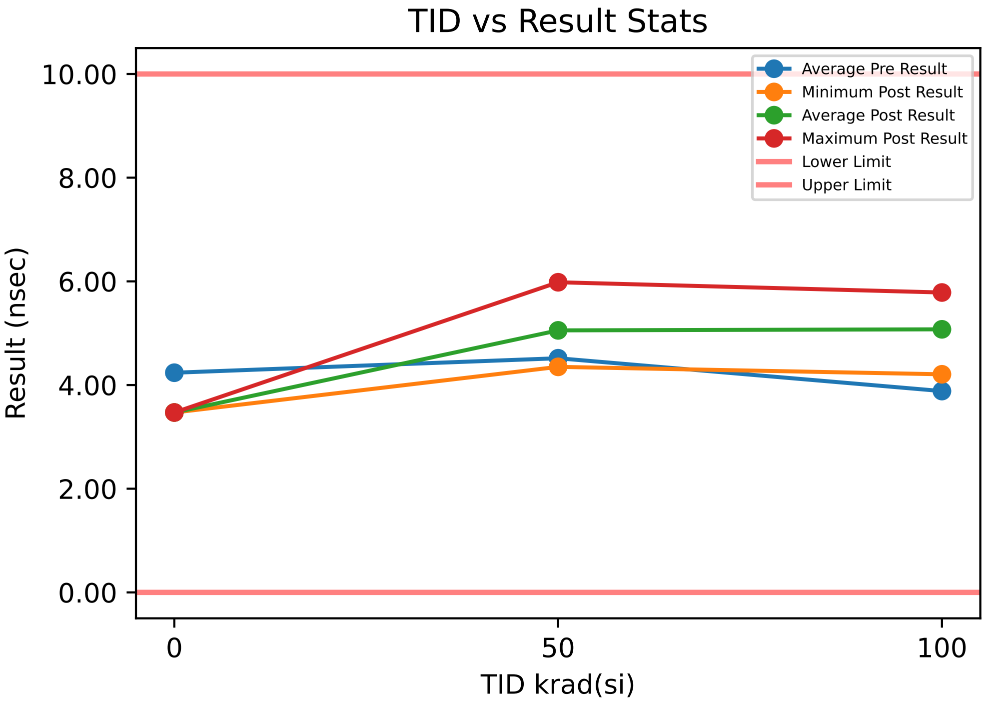
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

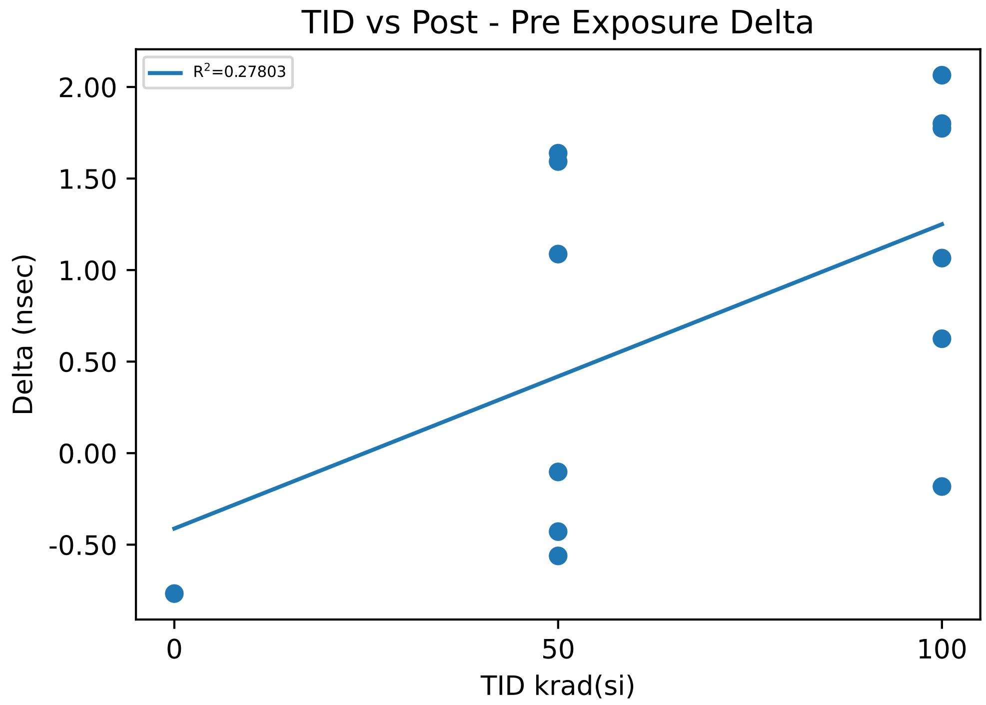
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	101.54	98.668	-2.8704
60	50	Biased	100.48	95.34	-5.1356
61	50	Biased	100.7	97.078	-3.6212
63	100	Biased	100.87	94.677	-6.1904
64	100	Biased	101.64	94.338	-7.3025
65	100	Biased	104.03	96.5	-7.5302
66	50	Unbiased	101.34	96.181	-5.162
67	50	Unbiased	101.28	97.919	-3.3624
68	50	Unbiased	101.69	97.592	-4.102
69	100	Unbiased	103.75	95.739	-8.0126
70	100	Unbiased	103.65	95.096	-8.5549
71	100	Unbiased	103.27	96.08	-7.1926
72	0	Control	102.64	102.05	-0.5929

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	102.64	102.64	102.64		102.05	102.05	102.05		-0.5929	-0.5929	-0.5929	
50	100.48	101.17	101.69	0.48081	95.34	97.13	98.668	1.2091	-5.162	-4.0423	-2.8704	0.94504
100	100.87	102.87	104.03	1.2976	94.338	95.405	96.5	0.84025	-8.5549	-7.4639	-6.1904	0.80215

Device Test: 96.5 DLH Dead Time Min 1MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

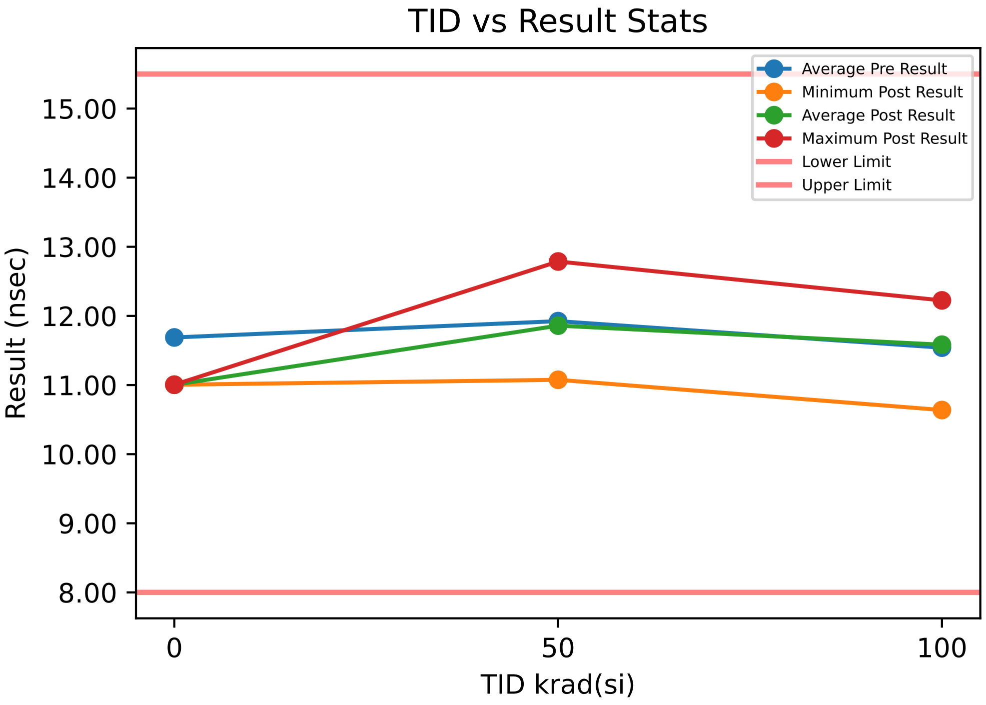
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

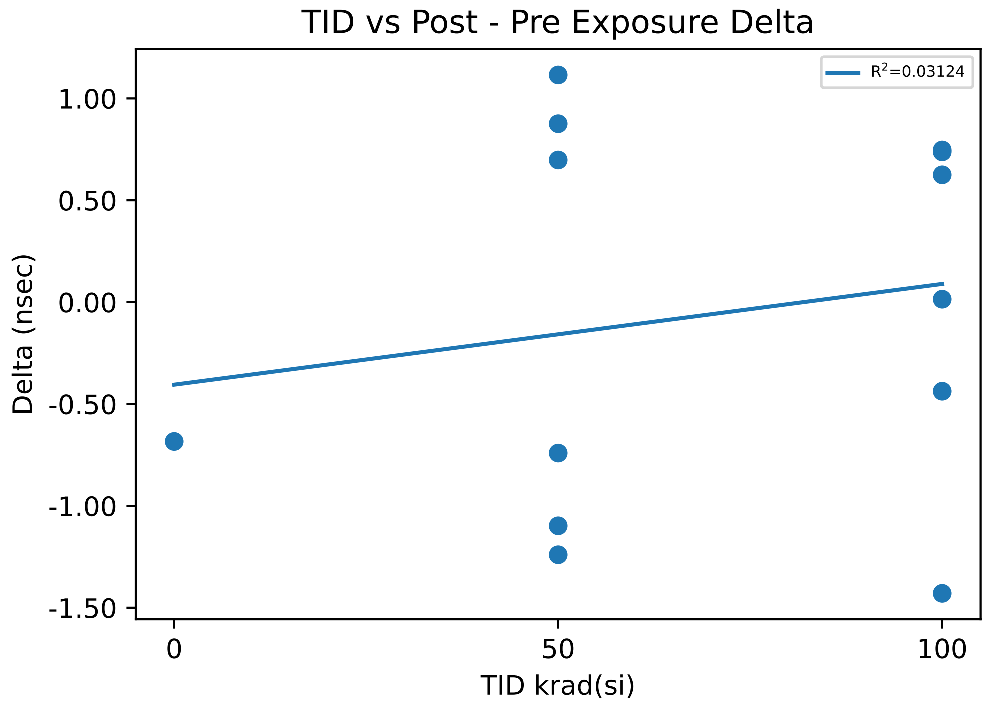
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.3442	5.9826	1.6384
60	50	Biased	5.0869	4.5256	-0.5613
61	50	Biased	4.5447	5.6321	1.0874
63	100	Biased	3.985	5.7851	1.8001
64	100	Biased	4.6112	5.6766	1.0654
65	100	Biased	3.6713	4.2962	0.6249
66	50	Unbiased	4.7795	4.3508	-0.4287
67	50	Unbiased	3.4798	5.0727	1.5929
68	50	Unbiased	4.866	4.7634	-0.1026
69	100	Unbiased	3.8842	5.6585	1.7743
70	100	Unbiased	4.3896	4.2073	-0.1823
71	100	Unbiased	2.7611	4.8255	2.0644
72	0	Control	4.2376	3.4704	-0.7672

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.2376	4.2376	4.2376		3.4704	3.4704	3.4704		-0.7672	-0.7672	-0.7672	
50	3.4798	4.5168	5.0869	0.56954	4.3508	5.0545	5.9826	0.64109	-0.5613	0.53768	1.6384	1.0177
100	2.7611	3.8837	4.6112	0.6482	4.2073	5.0749	5.7851	0.72503	-0.1823	1.1911	2.0644	0.8598

Device Test: 96.6 DLH Dead Time Small 1MHz VIN_12V





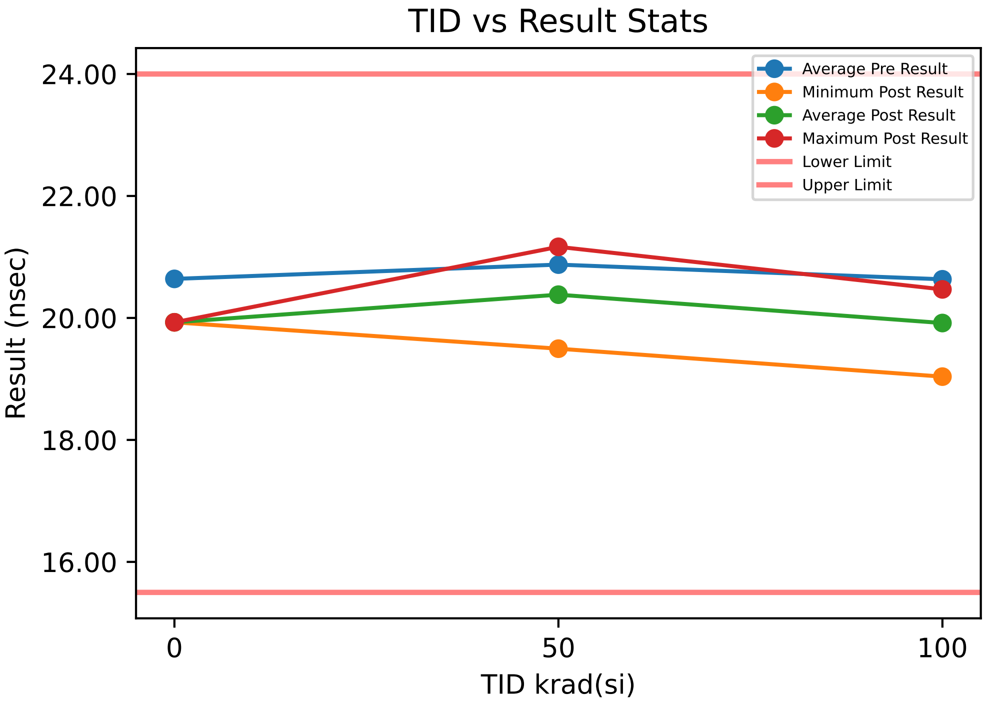
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

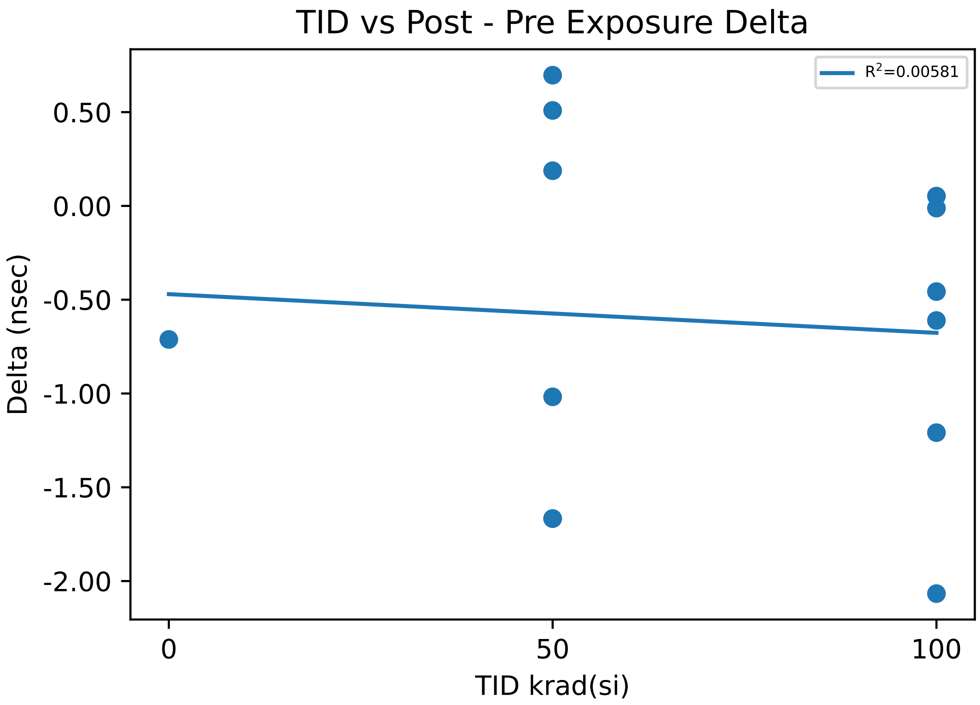
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	11.672	12.787	1.1152
60	50	Biased	12.316	11.076	-1.24
61	50	Biased	11.847	12.545	0.6978
63	100	Biased	11.456	12.203	0.747
64	100	Biased	11.998	12.012	0.0144
65	100	Biased	11.566	11.129	-0.4373
66	50	Unbiased	12.282	11.184	-1.0979
67	50	Unbiased	11.066	11.942	0.8758
68	50	Unbiased	12.363	11.622	-0.7408
69	100	Unbiased	11.6	12.225	0.625
70	100	Unbiased	12.068	10.639	-1.4295
71	100	Unbiased	10.557	11.295	0.7376
72	0	Control	11.688	11.005	-0.6839

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.688	11.688	11.688		11.005	11.005	11.005		-0.6839	-0.6839	-0.6839	
50	11.066	11.924	12.363	0.50579	11.076	11.859	12.787	0.70211	-1.24	-0.064983	1.1152	1.0737
100	10.557	11.541	12.068	0.54144	10.639	11.584	12.225	0.65751	-1.4295	0.042867	0.747	0.86216

Device Test: 96.7 DLH Dead Time Mid 1MHz VIN_12V





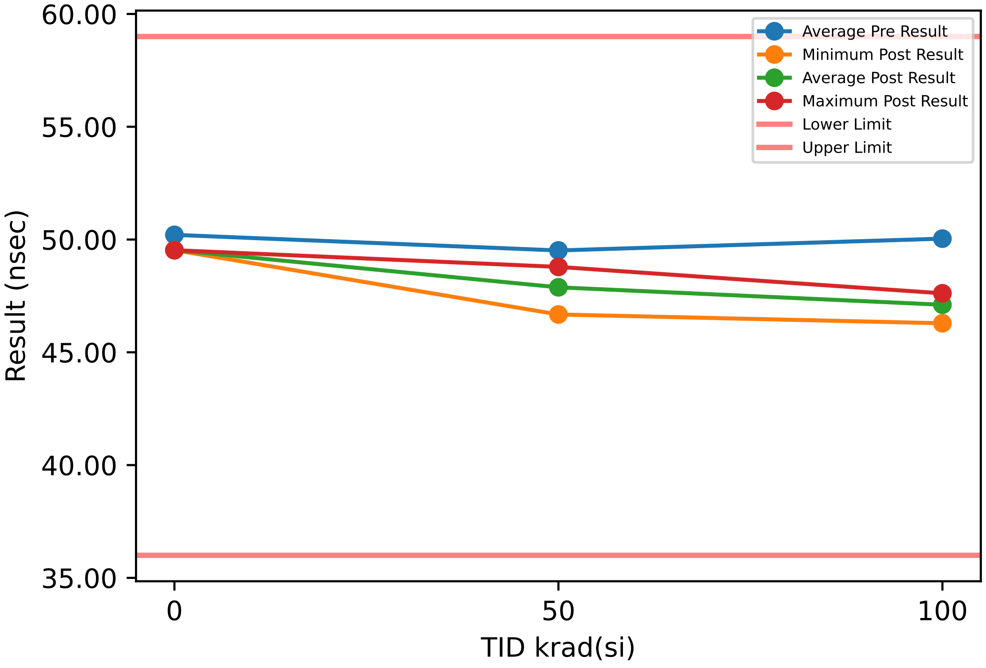
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

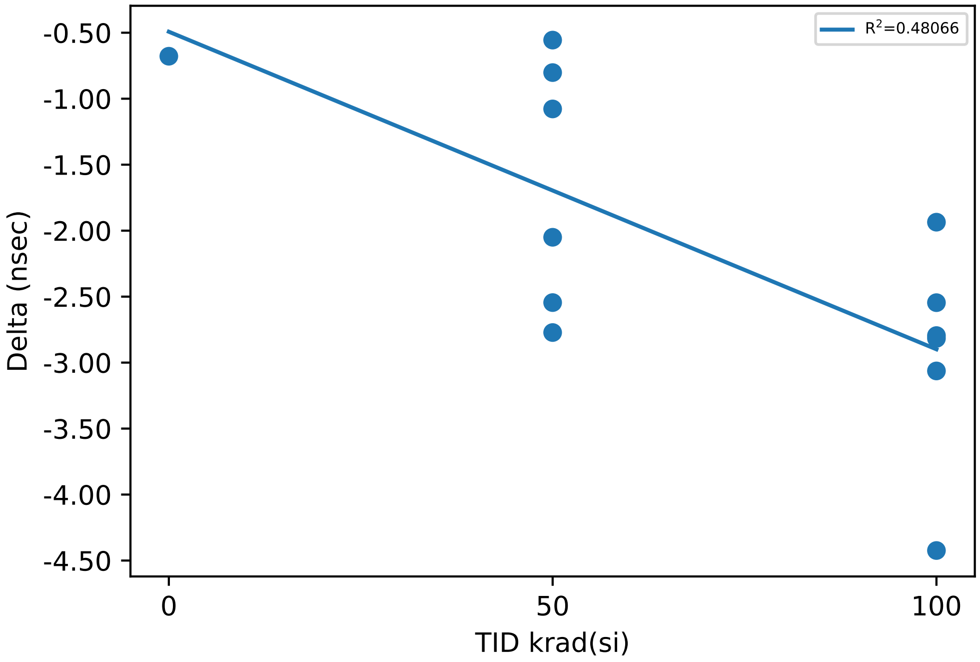
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	20.469	21.166	0.6969
60	50	Biased	21.163	19.496	-1.667
61	50	Biased	20.723	20.91	0.1876
63	100	Biased	20.283	20.272	-0.0117
64	100	Biased	20.881	20.27	-0.6108
65	100	Biased	20.83	19.621	-1.2088
66	50	Unbiased	21.28	19.614	-1.6668
67	50	Unbiased	20.255	20.764	0.509
68	50	Unbiased	21.357	20.339	-1.0178
69	100	Unbiased	20.925	20.468	-0.4567
70	100	Unbiased	21.105	19.038	-2.0668
71	100	Unbiased	19.779	19.832	0.0524
72	0	Control	20.64	19.929	-0.7119

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.64	20.64	20.64		19.929	19.929	19.929		-0.7119	-0.7119	-0.7119	
50	20.255	20.875	21.357	0.45874	19.496	20.382	21.166	0.69526	-1.667	-0.49302	0.6969	1.0876
100	19.779	20.634	21.105	0.50181	19.038	19.917	20.468	0.53326	-2.0668	-0.71707	0.0524	0.80403

Device Test: 96.8 DLH Dead Time Large 1MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

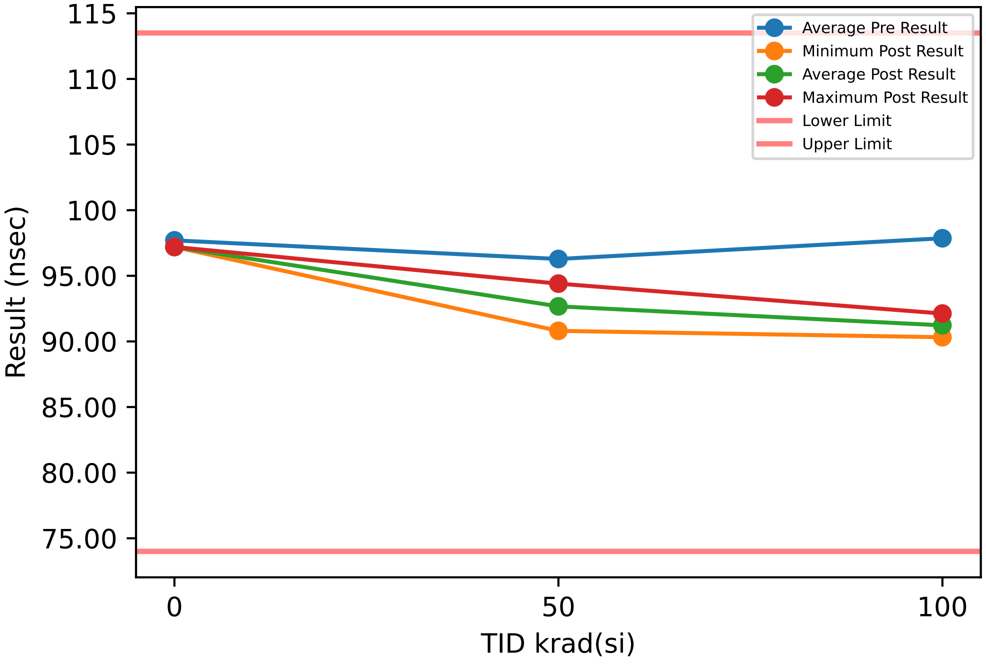
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

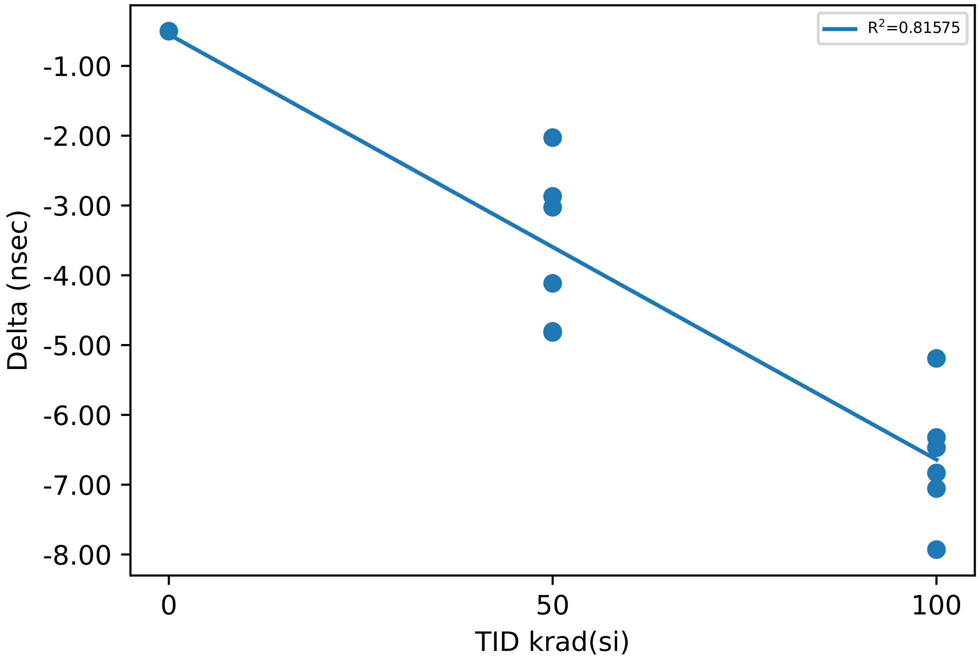
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	49.343	48.787	-0.5559
60	50	Biased	49.45	46.677	-2.7721
61	50	Biased	49.208	48.131	-1.0776
63	100	Biased	48.946	47.01	-1.9358
64	100	Biased	49.844	47.027	-2.8165
65	100	Biased	50.59	47.527	-3.0631
66	50	Unbiased	49.933	47.388	-2.5451
67	50	Unbiased	49.247	48.445	-0.8021
68	50	Unbiased	49.914	47.864	-2.0502
69	100	Unbiased	50.41	47.615	-2.7951
70	100	Unbiased	50.712	46.288	-4.424
71	100	Unbiased	49.73	47.185	-2.5457
72	0	Control	50.207	49.529	-0.6782

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.207	50.207	50.207		49.529	49.529	49.529		-0.6782	-0.6782	-0.6782	
50	49.208	49.516	49.933	0.3268	46.677	47.882	48.787	0.76059	-2.7721	-1.6338	-0.5559	0.94473
100	48.946	50.039	50.712	0.66683	46.288	47.109	47.615	0.47488	-4.424	-2.93	-1.9358	0.82667

Device Test: 96.9 DLH Dead Time Max 1MHz VIN_12V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

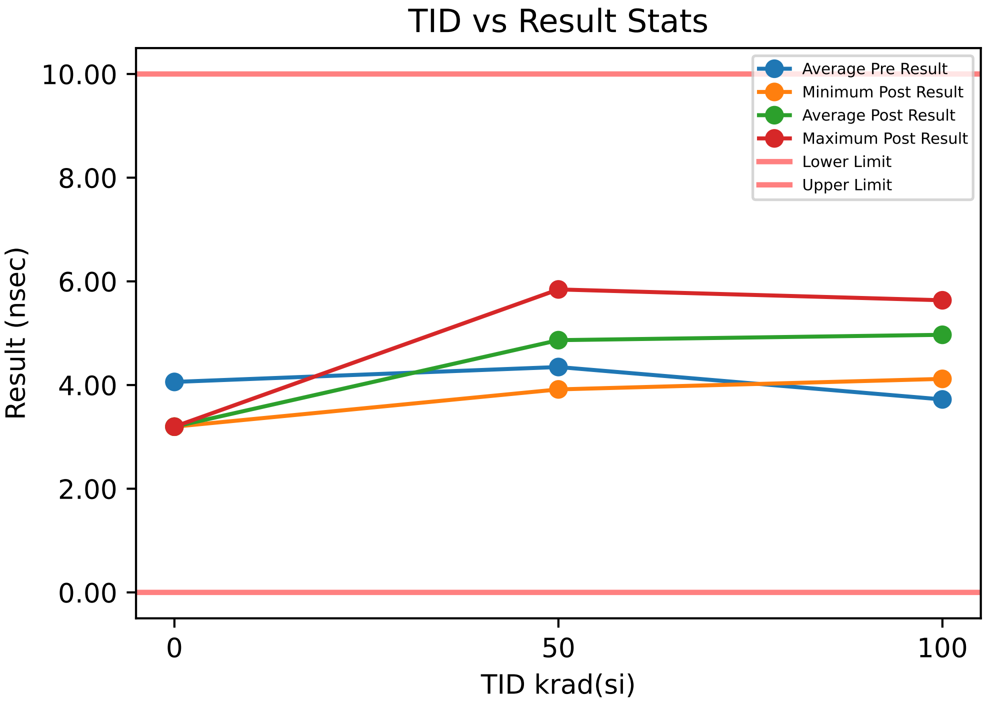
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

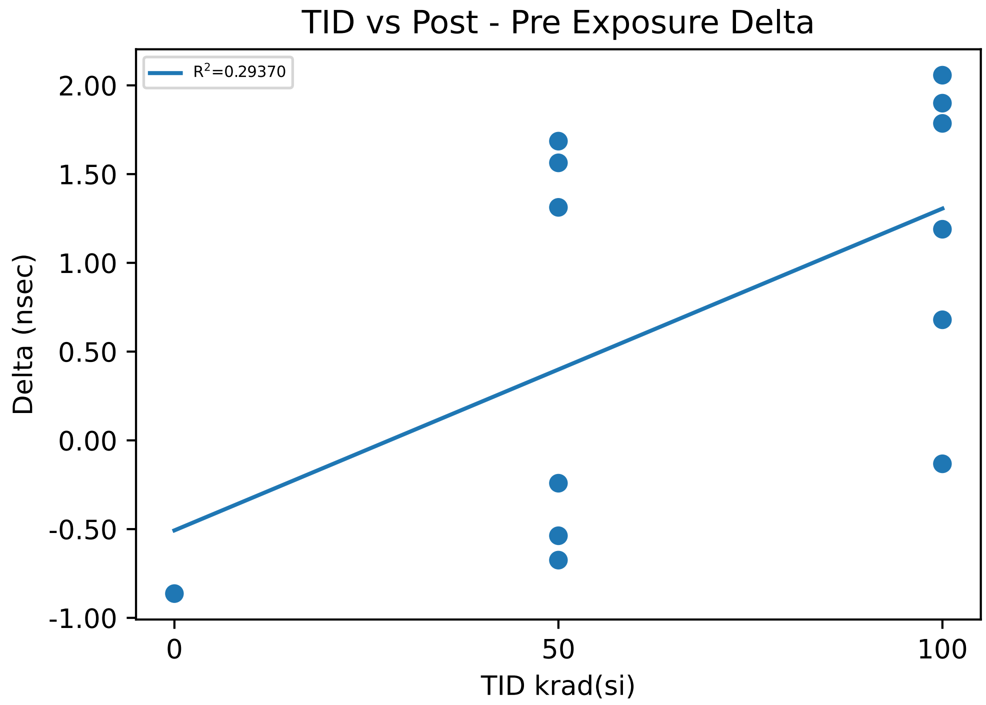
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	96.431	94.404	-2.0276
60	50	Biased	95.623	90.804	-4.8186
61	50	Biased	95.804	92.778	-3.0256
63	100	Biased	95.751	90.56	-5.1907
64	100	Biased	96.79	90.319	-6.4703
65	100	Biased	98.955	92.124	-6.8316
66	50	Unbiased	96.655	91.852	-4.8037
67	50	Unbiased	96.349	93.479	-2.8698
68	50	Unbiased	96.828	92.712	-4.1154
69	100	Unbiased	98.726	91.671	-7.0549
70	100	Unbiased	98.69	90.76	-7.9298
71	100	Unbiased	98.245	91.921	-6.3233
72	0	Control	97.701	97.197	-0.5031

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.701	97.701	97.701		97.197	97.197	97.197		-0.5031	-0.5031	-0.5031	
50	95.623	96.282	96.828	0.47474	90.804	92.671	94.404	1.2509	-4.8186	-3.6101	-2.0276	1.1432
100	95.751	97.86	98.955	1.2946	90.319	91.226	92.124	0.77068	-7.9298	-6.6334	-5.1907	0.90573

Device Test: 97.0 DLH Dead Time Min 500kHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

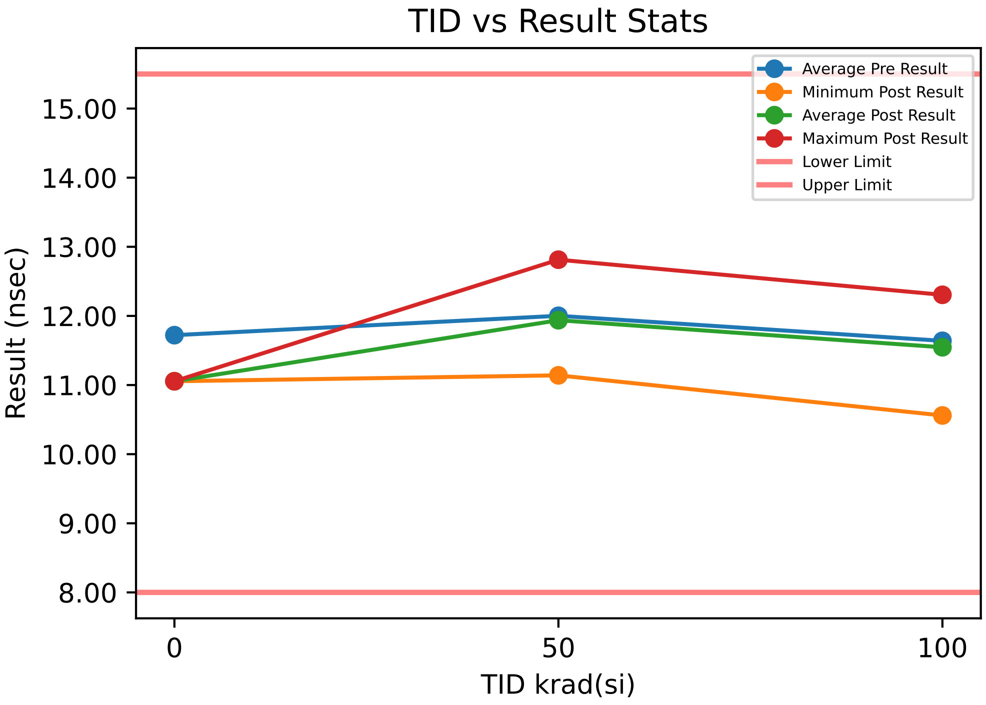
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

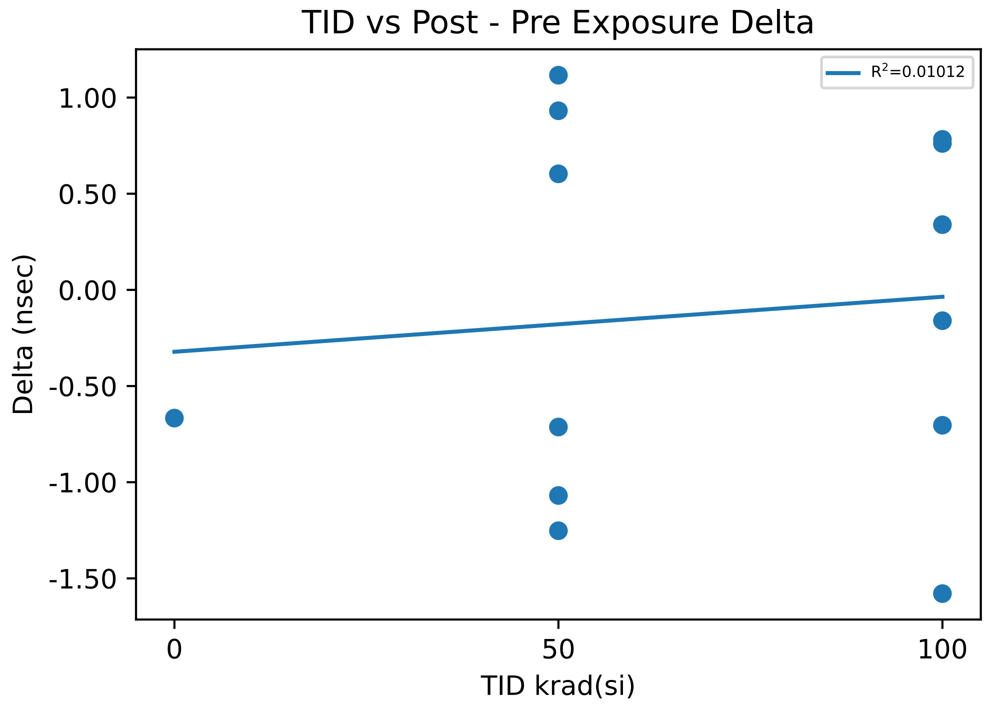
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.1587	5.8444	1.6857
60	50	Biased	4.9346	4.3972	-0.5374
61	50	Biased	4.3991	5.7117	1.3126
63	100	Biased	3.7968	5.5825	1.7857
64	100	Biased	4.4457	5.6351	1.1894
65	100	Biased	3.5363	4.2156	0.6793
66	50	Unbiased	4.5904	3.9157	-0.6747
67	50	Unbiased	3.2644	4.8278	1.5634
68	50	Unbiased	4.7381	4.4967	-0.2414
69	100	Unbiased	3.6423	5.5419	1.8996
70	100	Unbiased	4.251	4.1189	-0.1321
71	100	Unbiased	2.6621	4.7193	2.0572
72	0	Control	4.06	3.1967	-0.8633

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.06	4.06	4.06		3.1967	3.1967	3.1967		-0.8633	-0.8633	-0.8633	
50	3.2644	4.3476	4.9346	0.59459	3.9157	4.8656	5.8444	0.76592	-0.6747	0.51803	1.6857	1.1136
100	2.6621	3.7224	4.4457	0.62824	4.1189	4.9689	5.6351	0.70724	-0.1321	1.2465	2.0572	0.84853

Device Test: 97.1 DLH Dead Time Small 500kHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

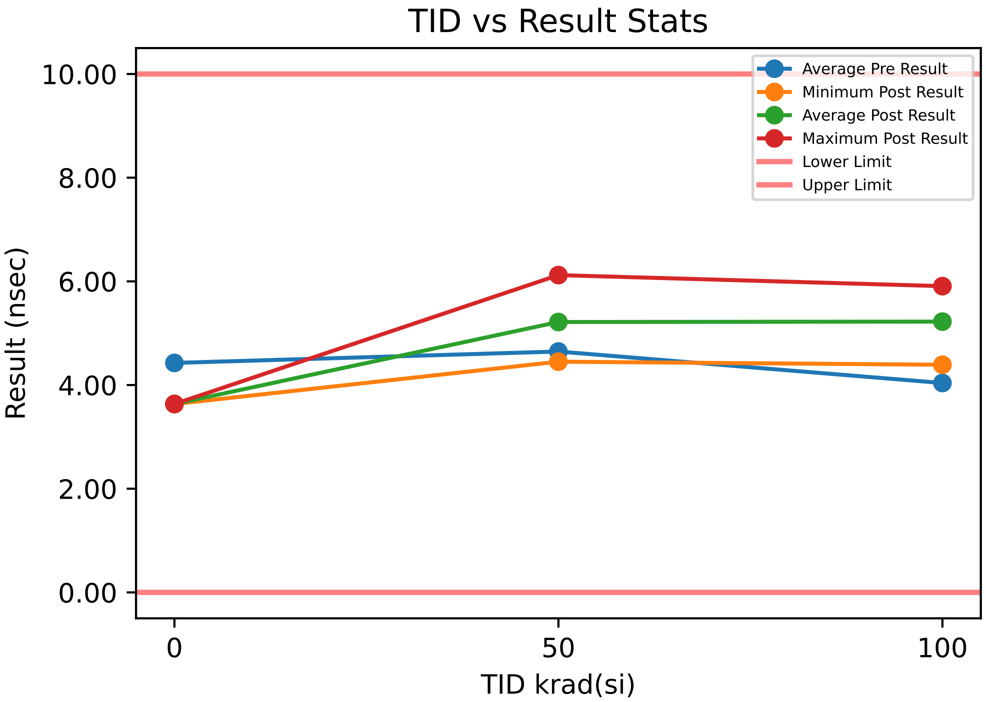
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

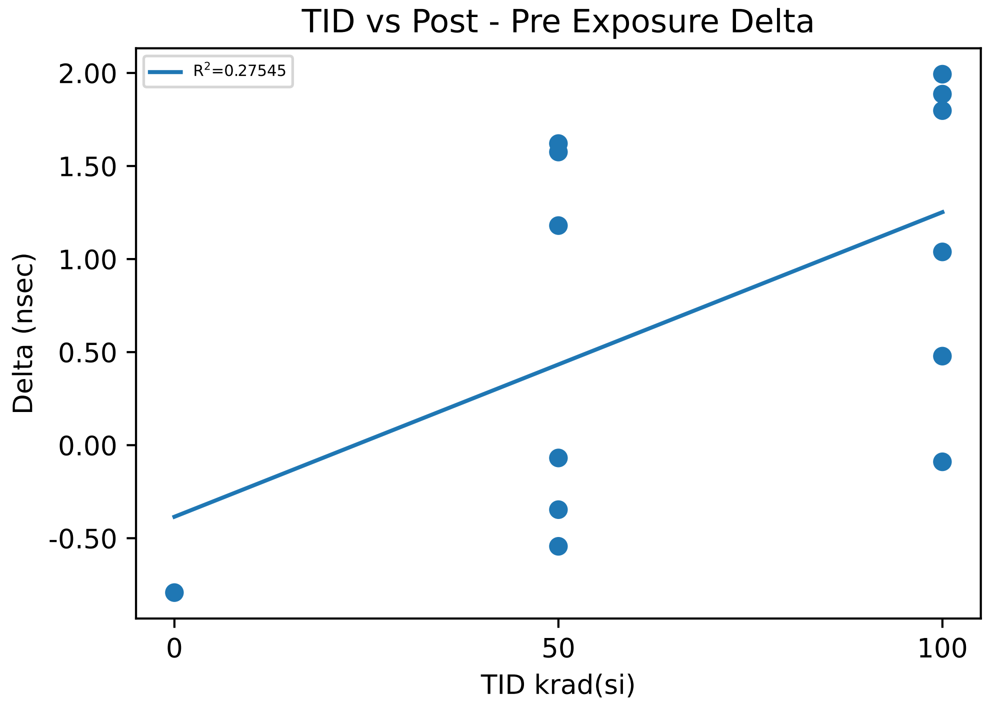
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	11.697	12.813	1.1163
60	50	Biased	12.393	11.14	-1.2523
61	50	Biased	11.888	12.492	0.6034
63	100	Biased	11.544	12.305	0.7614
64	100	Biased	12.074	11.914	-0.1601
65	100	Biased	11.68	10.976	-0.7039
66	50	Unbiased	12.374	11.305	-1.0691
67	50	Unbiased	11.145	12.076	0.9314
68	50	Unbiased	12.512	11.799	-0.713
69	100	Unbiased	11.727	12.066	0.3393
70	100	Unbiased	12.139	10.56	-1.5792
71	100	Unbiased	10.674	11.457	0.7827
72	0	Control	11.722	11.055	-0.6667

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.722	11.722	11.722		11.055	11.055	11.055		-0.6667	-0.6667	-0.6667	
50	11.145	12.002	12.512	0.5277	11.14	11.938	12.813	0.65544	-1.2523	-0.063883	1.1163	1.0652
100	10.674	11.64	12.139	0.52703	10.56	11.546	12.305	0.67648	-1.5792	-0.0933	0.7827	0.92415

Device Test: 97.10 DLH Dead Time Min 2MHz VIN_14V





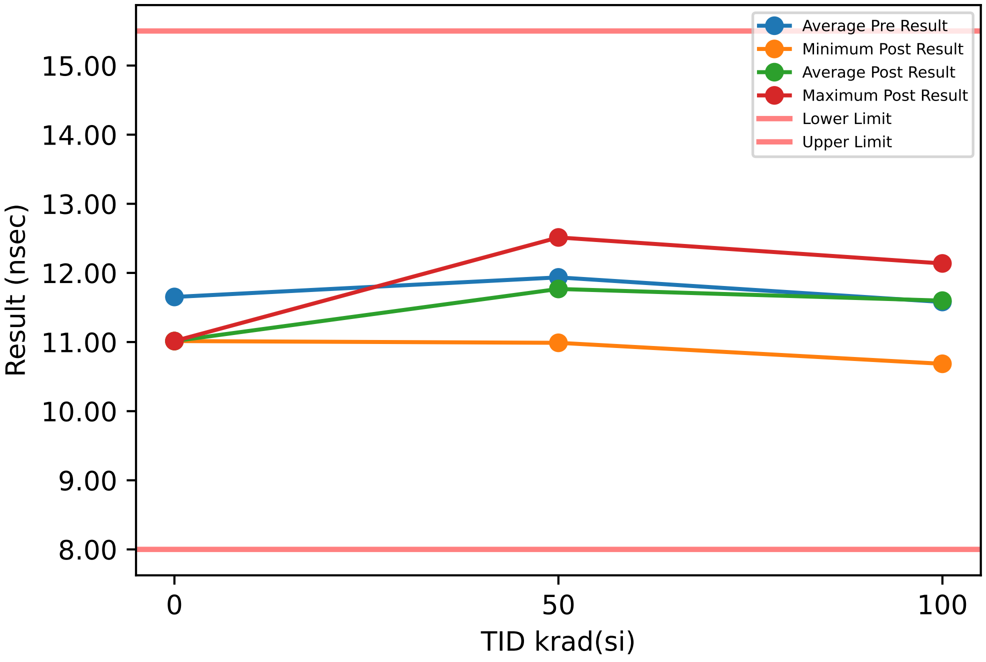
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

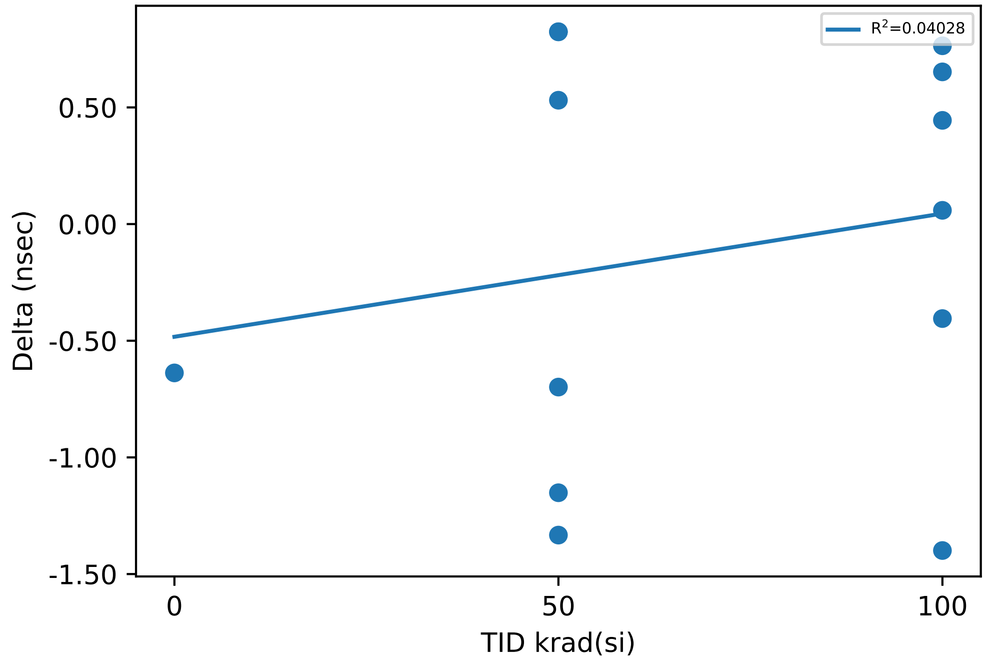
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.5001	6.1208	1.6207
60	50	Biased	5.2937	4.7501	-0.5436
61	50	Biased	4.7329	5.9128	1.1799
63	100	Biased	4.11	5.9077	1.7977
64	100	Biased	4.8377	5.8762	1.0385
65	100	Biased	3.9129	4.3913	0.4784
66	50	Unbiased	4.7973	4.4507	-0.3466
67	50	Unbiased	3.5941	5.1693	1.5752
68	50	Unbiased	4.9606	4.8918	-0.0688
69	100	Unbiased	3.8838	5.7701	1.8863
70	100	Unbiased	4.5623	4.4728	-0.0895
71	100	Unbiased	2.9295	4.9229	1.9934
72	0	Control	4.4264	3.6341	-0.7923

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4264	4.4264	4.4264		3.6341	3.6341	3.6341		-0.7923	-0.7923	-0.7923	
50	3.5941	4.6465	5.2937	0.57909	4.4507	5.2159	6.1208	0.66547	-0.5436	0.56947	1.6207	0.99747
100	2.9295	4.0394	4.8377	0.66148	4.3913	5.2235	5.9077	0.71266	-0.0895	1.1841	1.9934	0.85625

Device Test: 97.11 DLH Dead Time Small 2MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

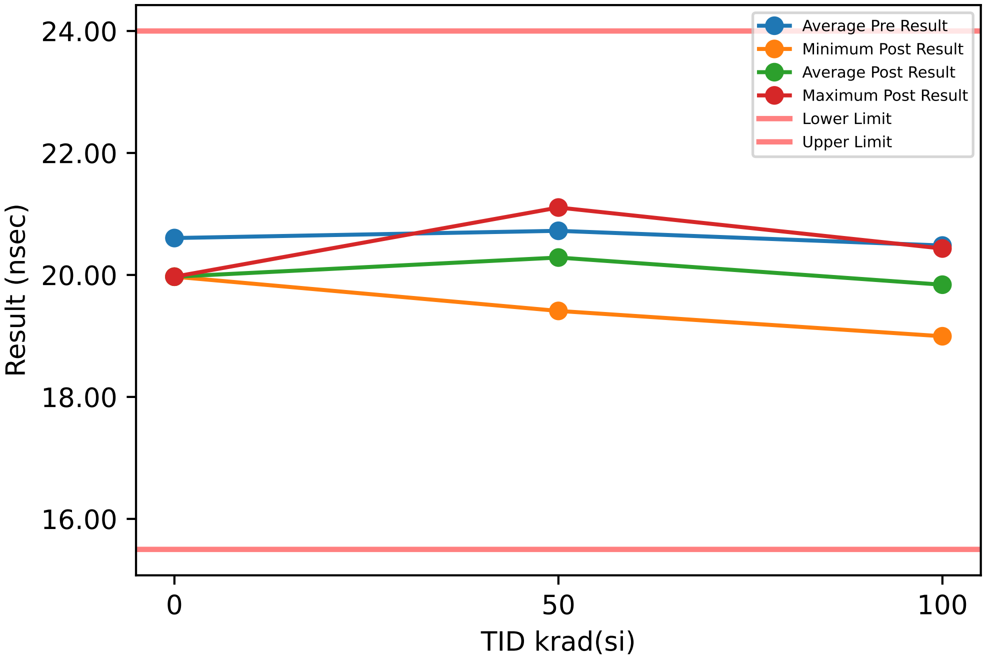
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	11.69	12.513	0.8238
60	50	Biased	12.322	10.989	-1.333
61	50	Biased	11.846	12.377	0.5308
63	100	Biased	11.485	12.137	0.6523
64	100	Biased	12.074	12.133	0.0589
65	100	Biased	11.611	11.206	-0.405
66	50	Unbiased	12.266	11.115	-1.1515
67	50	Unbiased	11.103	11.928	0.8244
68	50	Unbiased	12.385	11.686	-0.6986
69	100	Unbiased	11.576	12.021	0.4445
70	100	Unbiased	12.084	10.685	-1.3991
71	100	Unbiased	10.648	11.412	0.7642
72	0	Control	11.652	11.014	-0.6379

Test Statistics (nsec)

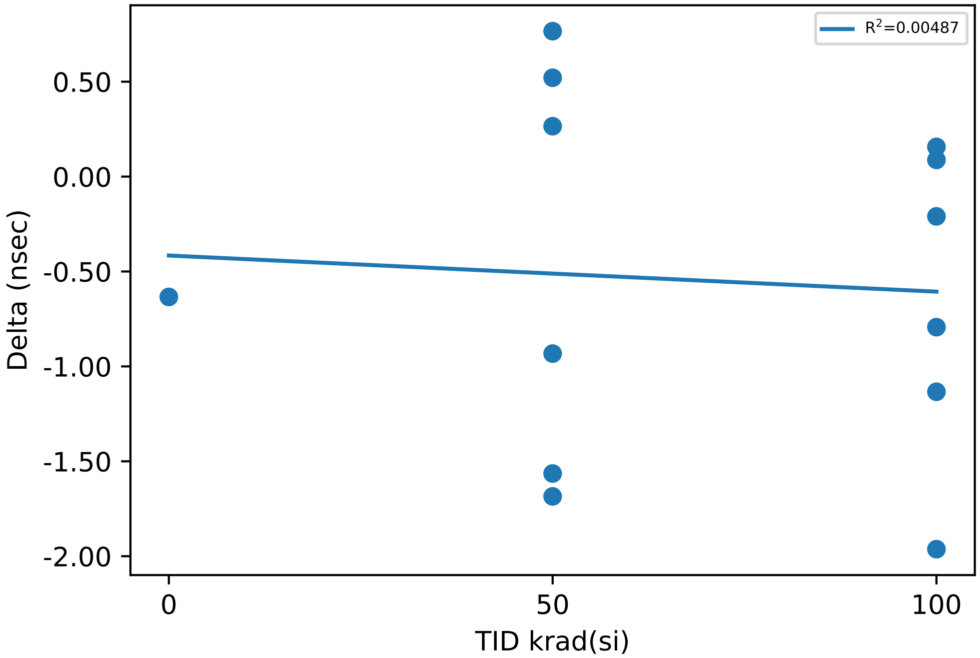
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.652	11.652	11.652		11.014	11.014	11.014		-0.6379	-0.6379	-0.6379	
50	11.103	11.935	12.385	0.49433	10.989	11.768	12.513	0.6313	-1.333	-0.16735	0.8244	1.0063
100	10.648	11.58	12.084	0.52491	10.685	11.599	12.137	0.59606	-1.3991	0.0193	0.7642	0.81607

Device Test: 97.12 DLH Dead Time Mid 2MHz VIN_14V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

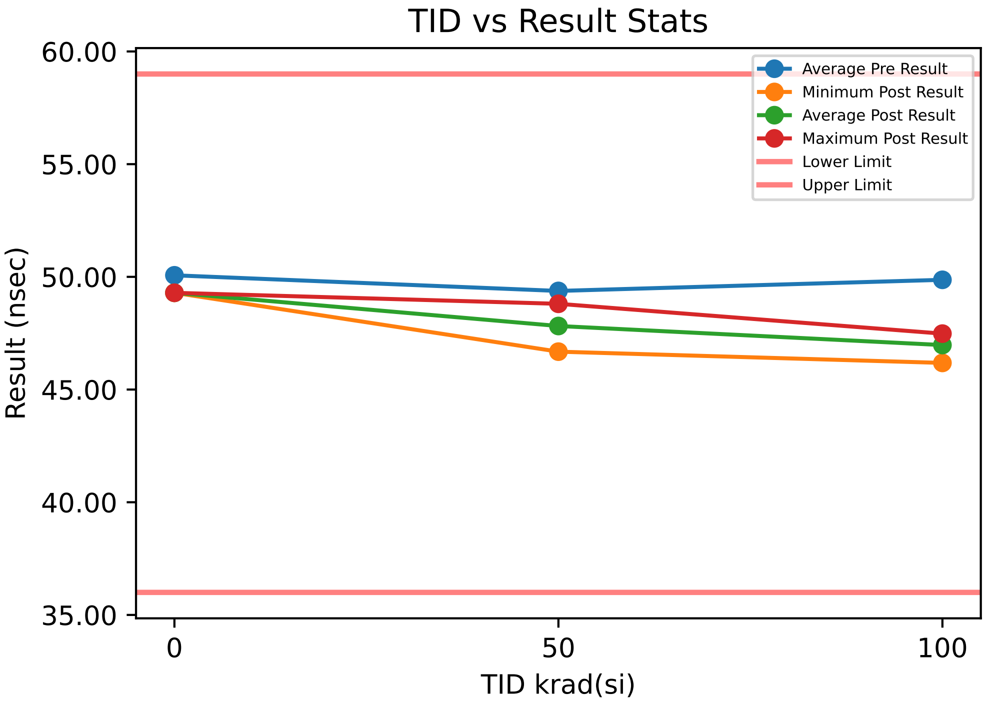
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	20.34	21.106	0.7662
60	50	Biased	21.095	19.41	-1.6849
61	50	Biased	20.557	20.823	0.2655
63	100	Biased	20.187	20.275	0.0879
64	100	Biased	20.833	20.04	-0.7931
65	100	Biased	20.66	19.526	-1.1336
66	50	Unbiased	21.096	19.532	-1.5643
67	50	Unbiased	20.124	20.645	0.5208
68	50	Unbiased	21.131	20.198	-0.9325
69	100	Unbiased	20.643	20.434	-0.2095
70	100	Unbiased	20.958	18.995	-1.963
71	100	Unbiased	19.615	19.771	0.1566
72	0	Control	20.605	19.971	-0.634

Test Statistics (nsec)

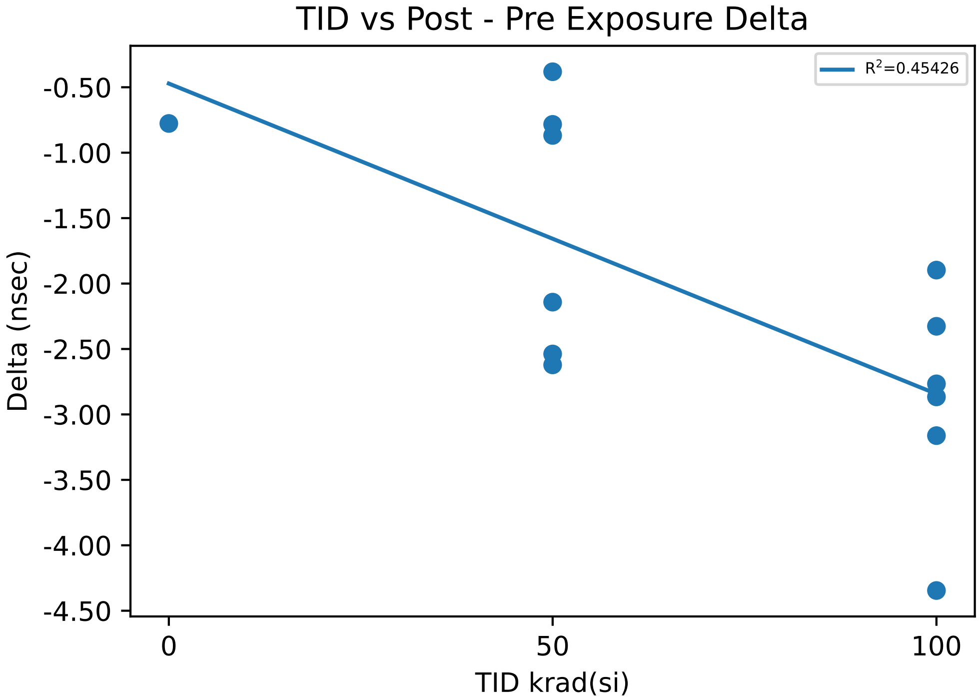
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.605	20.605	20.605		19.971	19.971	19.971		-0.634	-0.634	-0.634	
50	20.124	20.724	21.131	0.44205	19.41	20.285	21.106	0.69747	-1.6849	-0.4382	0.7662	1.0892
100	19.615	20.483	20.958	0.49926	18.995	19.84	20.434	0.52895	-1.963	-0.64245	0.1566	0.82062

Device Test: 97.13 DLH Dead Time Large 2MHz VIN_14V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



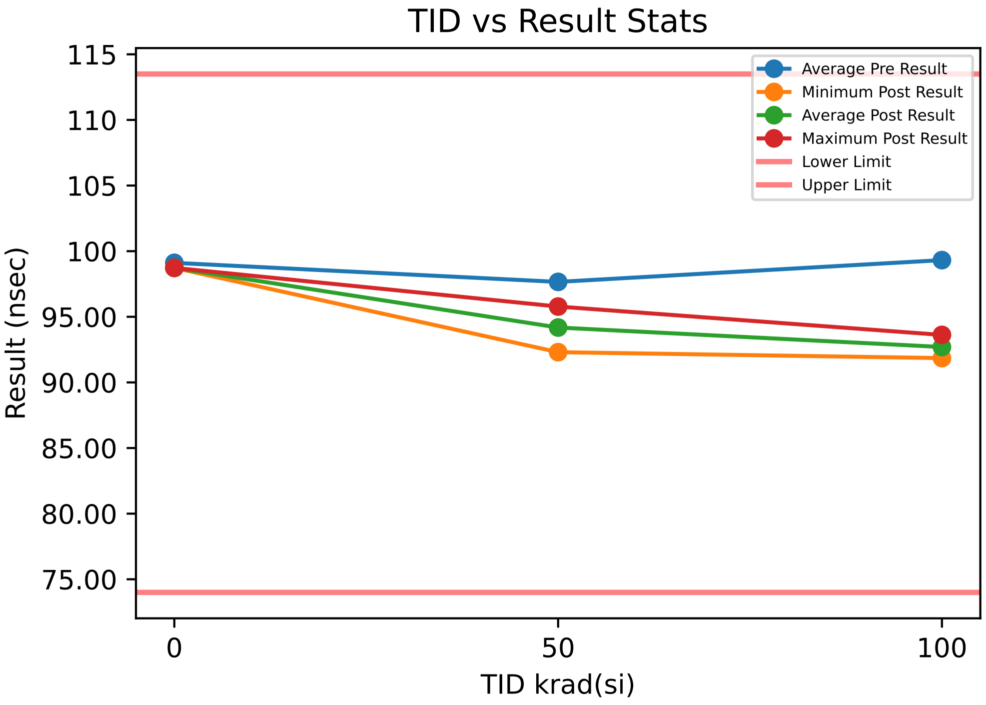
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

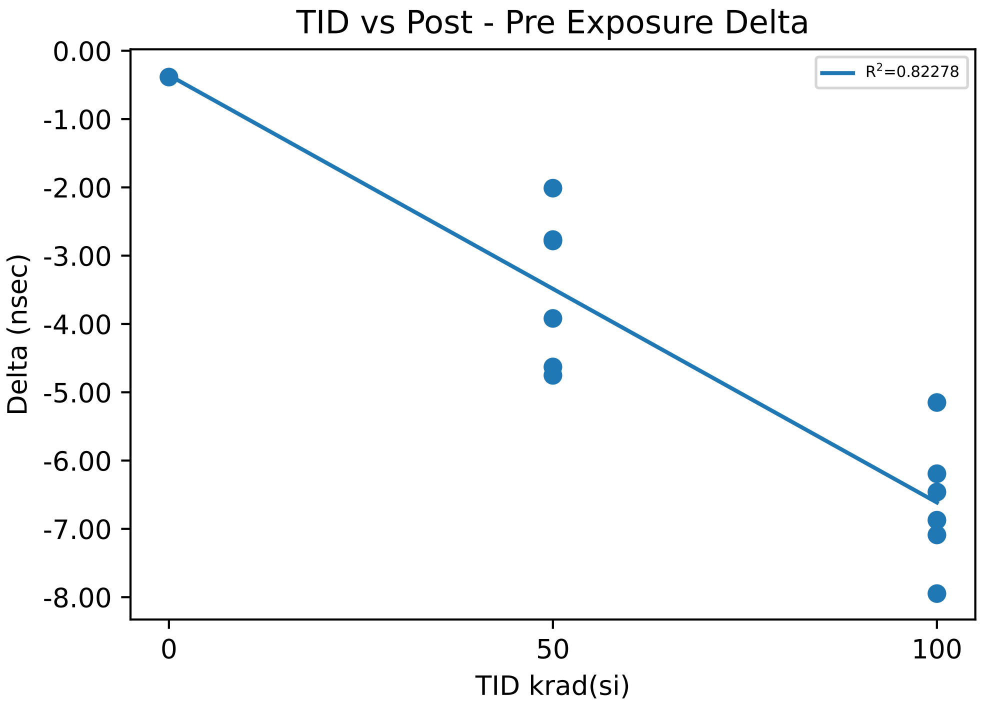
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	49.186	48.804	-0.3815
60	50	Biased	49.219	46.681	-2.5381
61	50	Biased	49.023	48.155	-0.8681
63	100	Biased	48.695	46.798	-1.8971
64	100	Biased	49.663	46.897	-2.7664
65	100	Biased	50.447	47.285	-3.162
66	50	Unbiased	49.907	47.285	-2.6215
67	50	Unbiased	49.132	48.348	-0.7836
68	50	Unbiased	49.785	47.643	-2.142
69	100	Unbiased	50.347	47.481	-2.8661
70	100	Unbiased	50.528	46.182	-4.3456
71	100	Unbiased	49.529	47.203	-2.3266
72	0	Control	50.069	49.292	-0.7767

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.069	50.069	50.069		49.292	49.292	49.292		-0.7767	-0.7767	-0.7767	
50	49.023	49.375	49.907	0.37247	46.681	47.819	48.804	0.77126	-2.6215	-1.5558	-0.3815	0.98919
100	48.695	49.868	50.528	0.71165	46.182	46.974	47.481	0.46272	-4.3456	-2.894	-1.8971	0.83807

Device Test: 97.14 DLH Dead Time Max 2MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

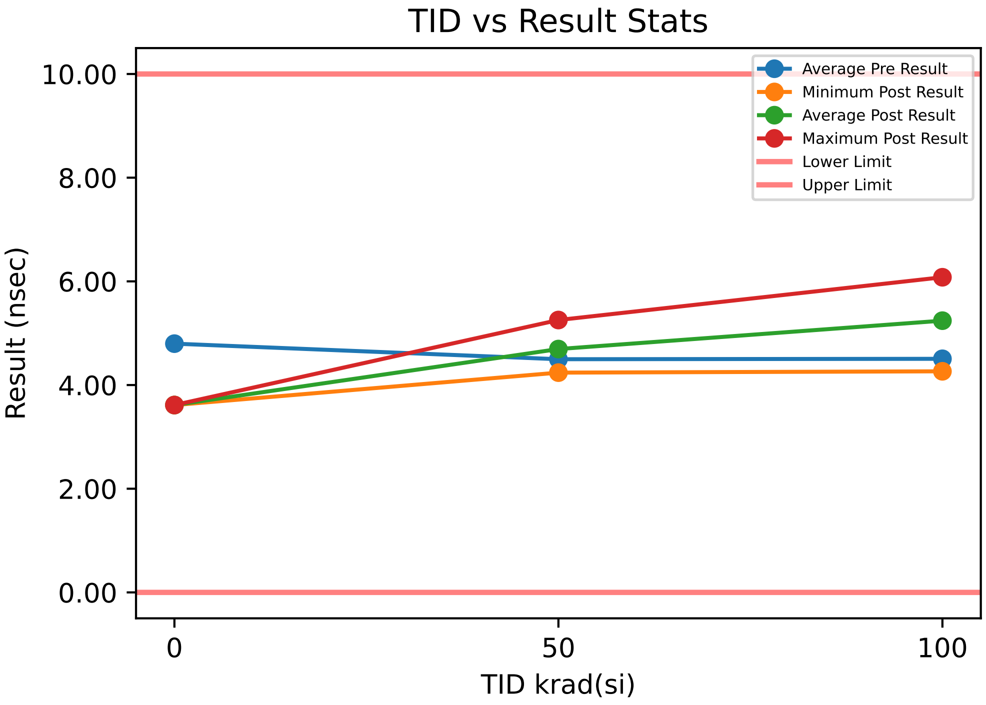
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

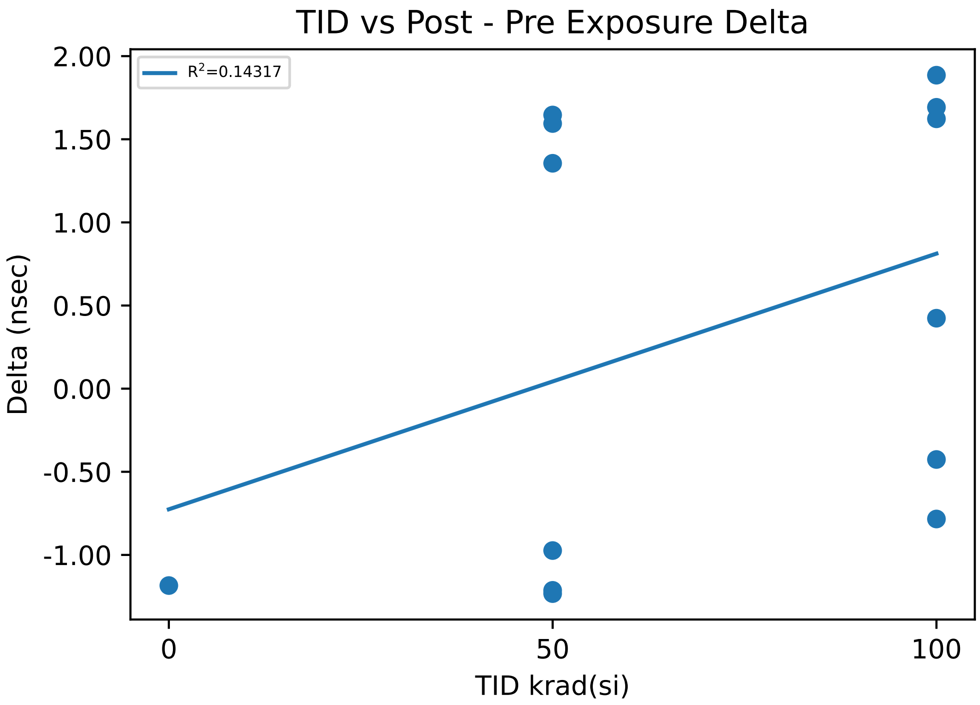
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	97.792	95.781	-2.0116
60	50	Biased	97.057	92.305	-4.7524
61	50	Biased	97.163	94.399	-2.7641
63	100	Biased	97.153	92.003	-5.1498
64	100	Biased	98.315	91.854	-6.461
65	100	Biased	100.49	93.62	-6.8726
66	50	Unbiased	98.055	93.426	-4.6292
67	50	Unbiased	97.784	95	-2.7847
68	50	Unbiased	98.105	94.187	-3.9187
69	100	Unbiased	100.06	92.972	-7.0886
70	100	Unbiased	100.18	92.236	-7.9477
71	100	Unbiased	99.703	93.51	-6.1926
72	0	Control	99.111	98.726	-0.385

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	99.111	99.111	99.111		98.726	98.726	98.726		-0.385	-0.385	-0.385	
50	97.057	97.659	98.105	0.44691	92.305	94.183	95.781	1.2139	-4.7524	-3.4768	-2.0116	1.1211
100	97.153	99.318	100.49	1.3055	91.854	92.699	93.62	0.77374	-7.9477	-6.6187	-5.1498	0.93975

Device Test: 97.19 DHL Dead Time Min 500kHz VIN_14V





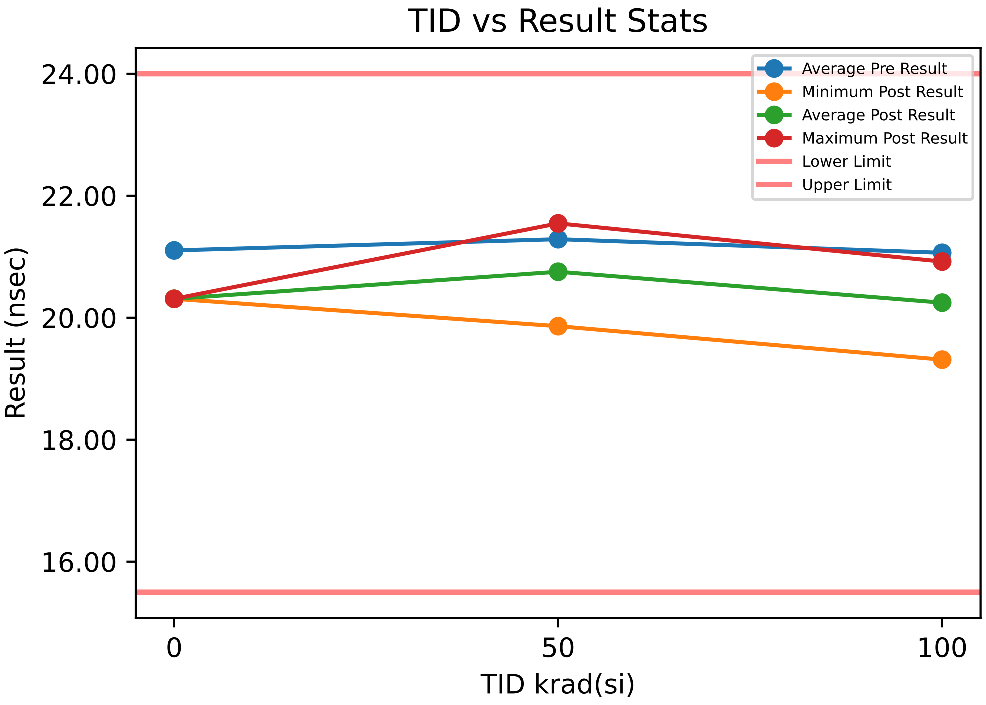
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

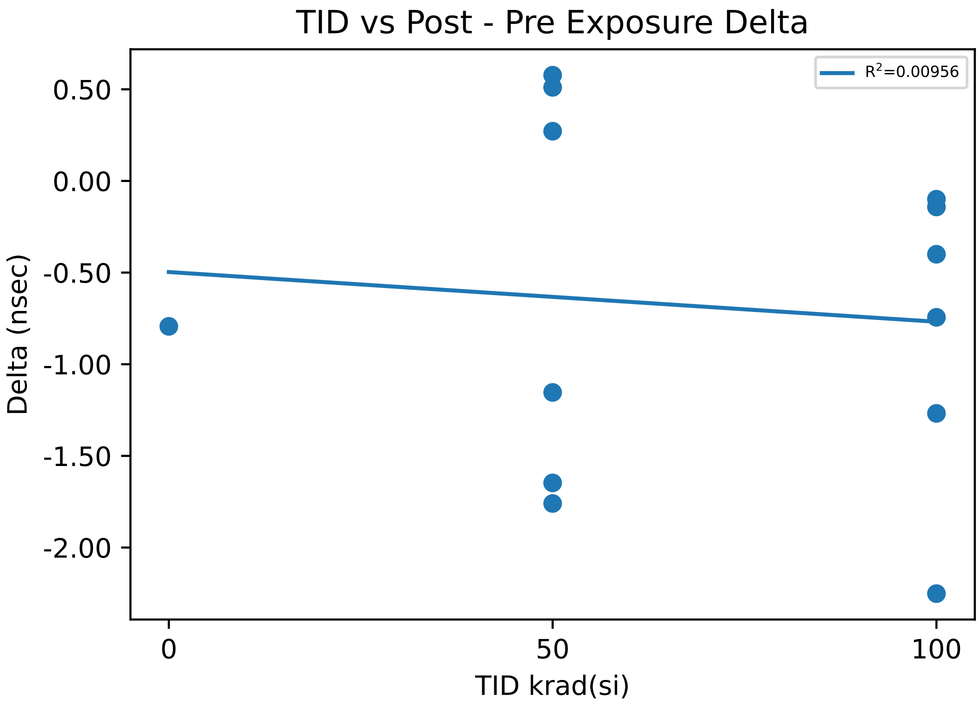
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.7015	5.057	1.3555
60	50	Biased	5.2192	4.2455	-0.9737
61	50	Biased	3.3129	4.9588	1.6459
63	100	Biased	3.6855	5.5708	1.8853
64	100	Biased	5.3482	4.9222	-0.426
65	100	Biased	3.8411	4.2648	0.4237
66	50	Unbiased	5.6235	4.4104	-1.2131
67	50	Unbiased	3.6595	5.2542	1.5947
68	50	Unbiased	5.4719	4.2393	-1.2326
69	100	Unbiased	4.3869	6.0791	1.6922
70	100	Unbiased	5.823	5.0391	-0.7839
71	100	Unbiased	3.9506	5.5736	1.623
72	0	Control	4.7983	3.6141	-1.1842

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.7983	4.7983	4.7983		3.6141	3.6141	3.6141		-1.1842	-1.1842	-1.1842	
50	3.3129	4.4981	5.6235	1.0466	4.2393	4.6942	5.2542	0.44812	-1.2326	0.19612	1.6459	1.4695
100	3.6855	4.5059	5.823	0.88111	4.2648	5.2416	6.0791	0.63516	-0.7839	0.73572	1.8853	1.1645

Device Test: 97.2 DLH Dead Time Mid 500kHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

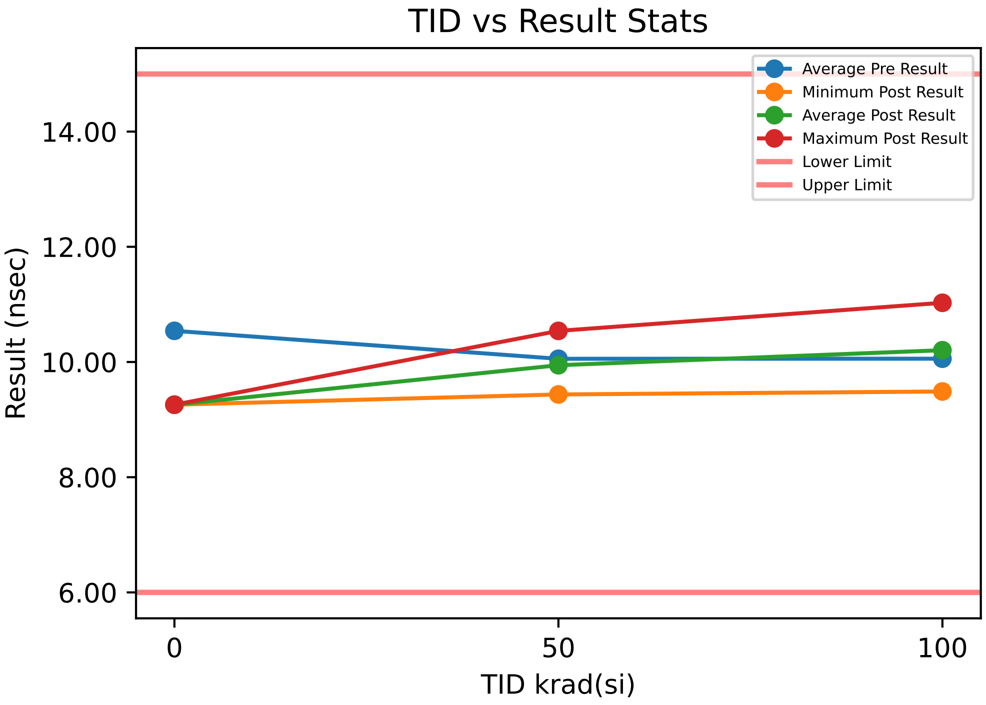
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

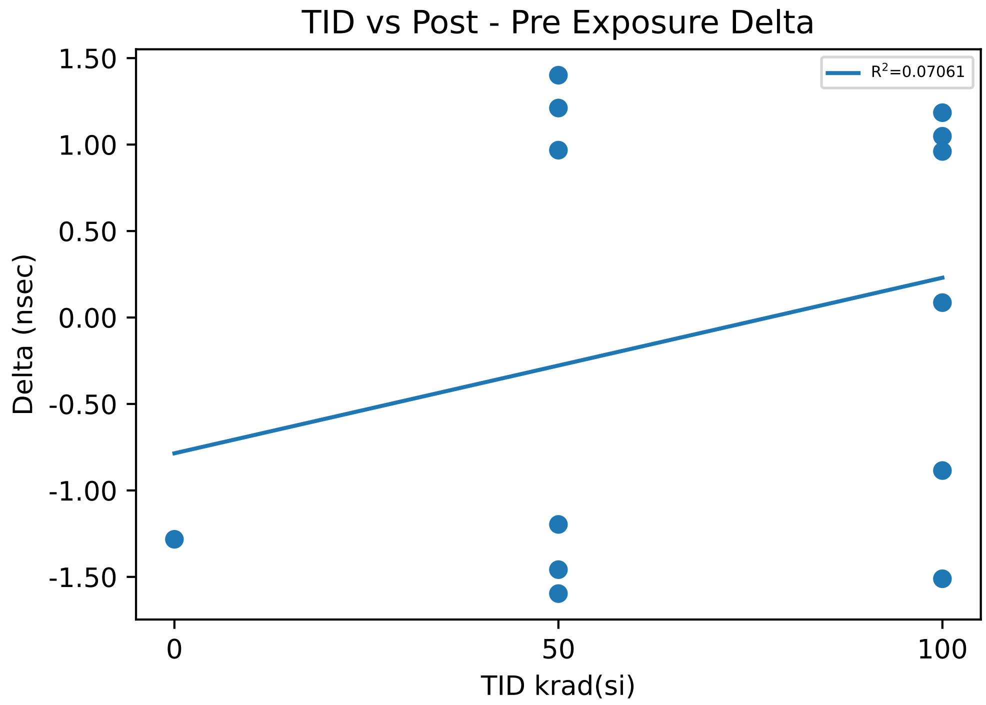
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	20.97	21.547	0.5769
60	50	Biased	21.62	19.861	-1.7597
61	50	Biased	21.158	21.43	0.2712
63	100	Biased	20.712	20.613	-0.0996
64	100	Biased	21.321	20.577	-0.744
65	100	Biased	21.229	19.961	-1.2682
66	50	Unbiased	21.634	19.987	-1.6474
67	50	Unbiased	20.551	21.061	0.5105
68	50	Unbiased	21.791	20.637	-1.1538
69	100	Unbiased	21.32	20.921	-0.4
70	100	Unbiased	21.563	19.312	-2.2513
71	100	Unbiased	20.239	20.097	-0.1419
72	0	Control	21.103	20.31	-0.7934

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.103	21.103	21.103		20.31	20.31	20.31		-0.7934	-0.7934	-0.7934	
50	20.551	21.287	21.791	0.47838	19.861	20.754	21.547	0.71826	-1.7597	-0.53372	0.5769	1.1045
100	20.239	21.064	21.563	0.49259	19.312	20.247	20.921	0.57877	-2.2513	-0.8175	-0.0996	0.82589

Device Test: 97.20 DHL Dead Time Small 500kHz VIN_14V





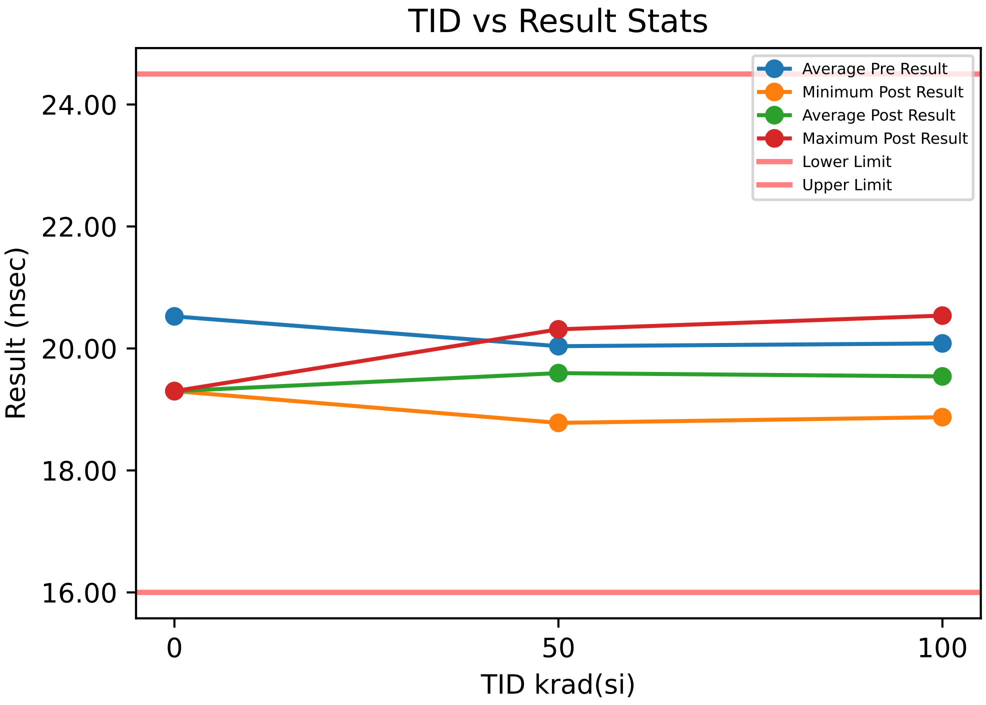
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

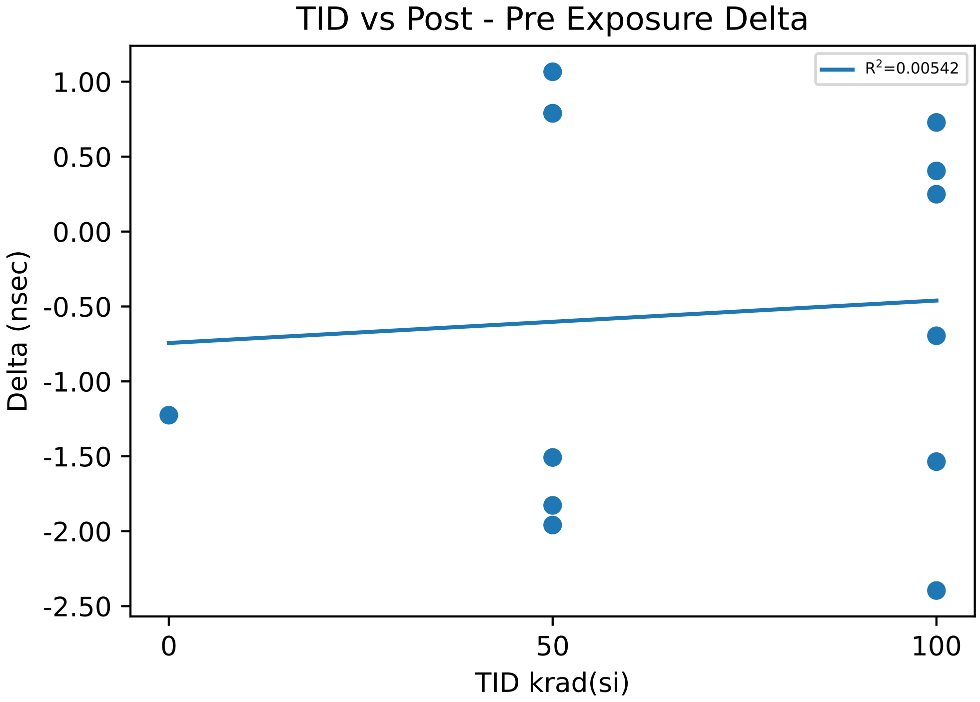
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	9.3444	10.312	0.9677
60	50	Biased	10.788	9.5913	-1.1966
61	50	Biased	8.919	10.32	1.4012
63	100	Biased	9.3246	10.509	1.1844
64	100	Biased	10.73	9.8453	-0.885
65	100	Biased	9.402	9.488	0.086
66	50	Unbiased	10.922	9.4636	-1.4581
67	50	Unbiased	9.3289	10.54	1.2113
68	50	Unbiased	11.033	9.4366	-1.5966
69	100	Unbiased	10.068	11.028	0.9602
70	100	Unbiased	11.32	9.8092	-1.5108
71	100	Unbiased	9.5001	10.548	1.0481
72	0	Control	10.541	9.2585	-1.2825

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.541	10.541	10.541		9.2585	9.2585	9.2585		-1.2825	-1.2825	-1.2825	
50	8.919	10.056	11.033	0.95581	9.4366	9.944	10.54	0.49902	-1.5966	-0.11185	1.4012	1.4422
100	9.3246	10.057	11.32	0.81538	9.488	10.205	11.028	0.58092	-1.5108	0.14715	1.1844	1.1284

Device Test: 97.21 DHL Dead Time Mid 500kHz VIN_14V





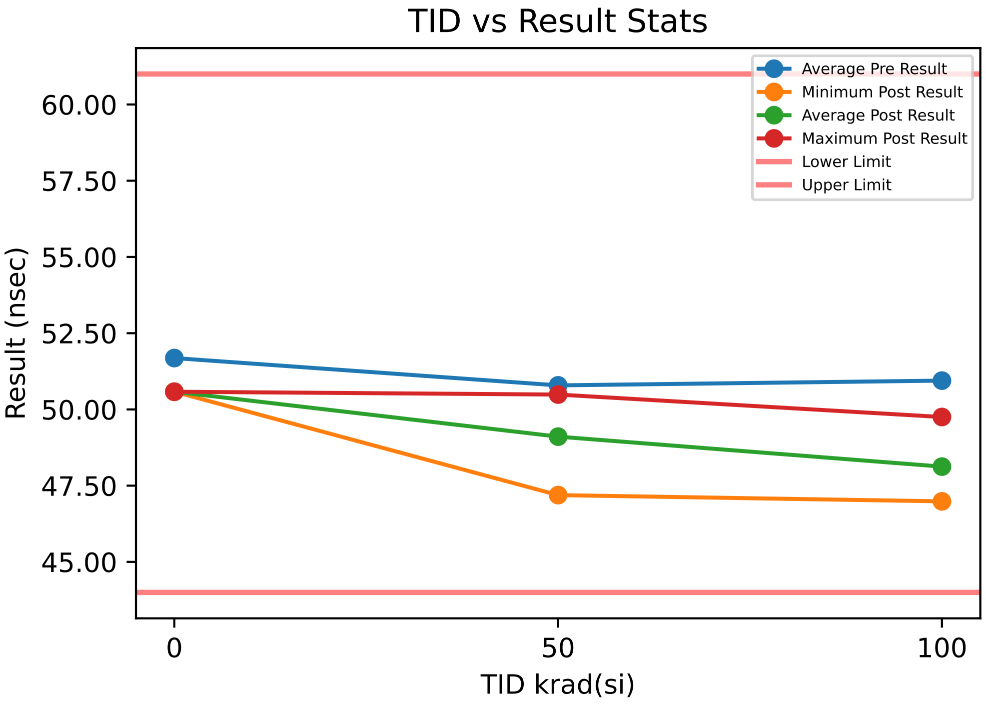
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

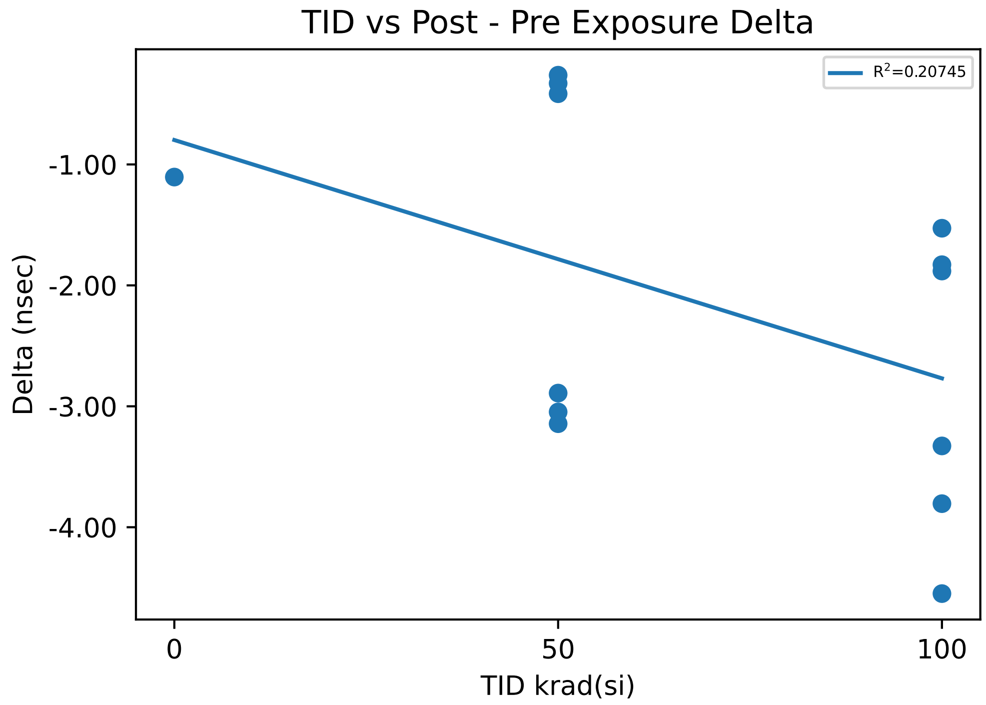
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	19.312	20.102	0.7894
60	50	Biased	20.604	19.097	-1.5077
61	50	Biased	19.096	20.163	1.0665
63	100	Biased	19.28	20.008	0.7283
64	100	Biased	20.642	19.107	-1.5355
65	100	Biased	19.575	18.88	-0.6955
66	50	Unbiased	20.607	18.78	-1.8276
67	50	Unbiased	19.524	20.313	0.7893
68	50	Unbiased	21.078	19.119	-1.9587
69	100	Unbiased	20.289	20.538	0.2491
70	100	Unbiased	21.269	18.873	-2.3957
71	100	Unbiased	19.438	19.843	0.4047
72	0	Control	20.526	19.3	-1.2256

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.526	20.526	20.526		19.3	19.3	19.3		-1.2256	-1.2256	-1.2256	
50	19.096	20.037	21.078	0.8252	18.78	19.596	20.313	0.66845	-1.9587	-0.44147	1.0665	1.4604
100	19.28	20.082	21.269	0.78494	18.873	19.542	20.538	0.68934	-2.3957	-0.54077	0.7283	1.2315

Device Test: 97.22 DHL Dead Time Large 500kHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

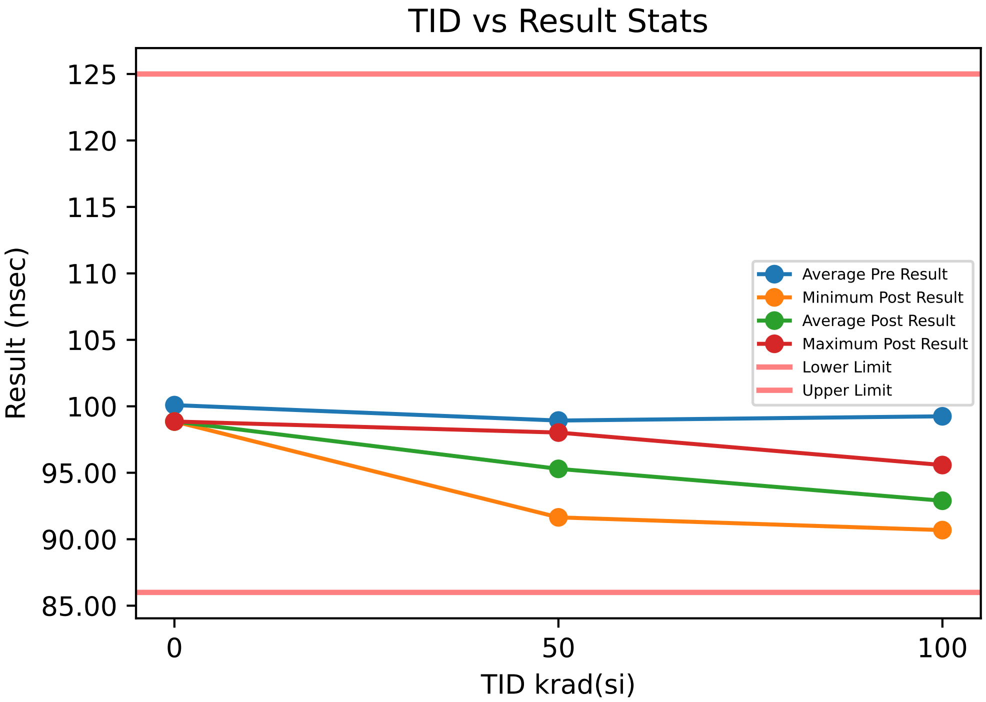
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

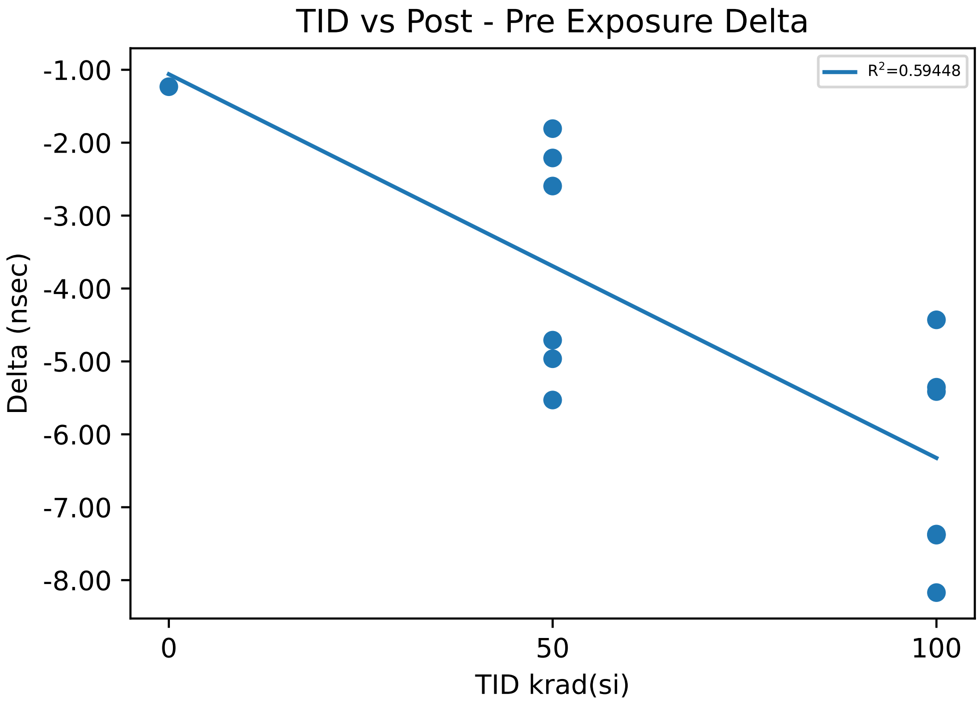
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	49.944	49.529	-0.4152
60	50	Biased	51.221	48.33	-2.8907
61	50	Biased	50.781	50.451	-0.3297
63	100	Biased	50.601	48.772	-1.8291
64	100	Biased	50.981	47.176	-3.8051
65	100	Biased	50.987	47.66	-3.3276
66	50	Unbiased	50.237	47.19	-3.0469
67	50	Unbiased	50.75	50.488	-0.2621
68	50	Unbiased	51.801	48.657	-3.1438
69	100	Unbiased	51.633	49.752	-1.8814
70	100	Unbiased	51.535	46.986	-4.5488
71	100	Unbiased	49.933	48.405	-1.5275
72	0	Control	51.685	50.58	-1.1044

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	51.685	51.685	51.685		50.58	50.58	50.58		-1.1044	-1.1044	-1.1044	
50	49.944	50.789	51.801	0.66792	47.19	49.108	50.488	1.2938	-3.1438	-1.6814	-0.2621	1.4772
100	49.933	50.945	51.633	0.62728	46.986	48.125	49.752	1.0544	-4.5488	-2.8199	-1.5275	1.245

Device Test: 97.23 DHL Dead Time Max 500kHz VIN_14V





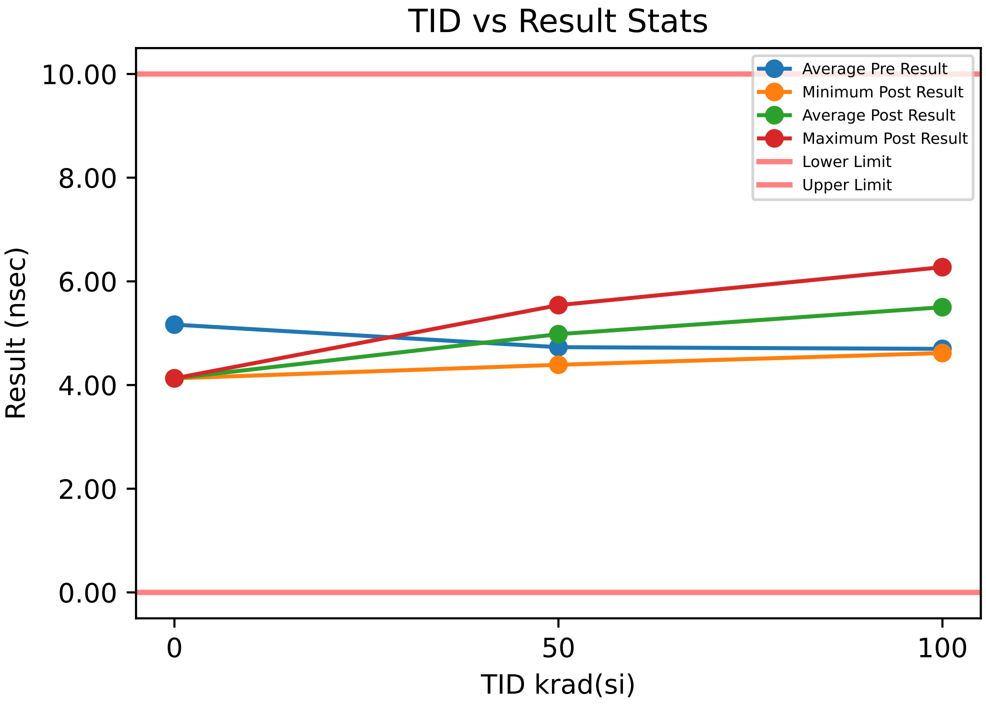
Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

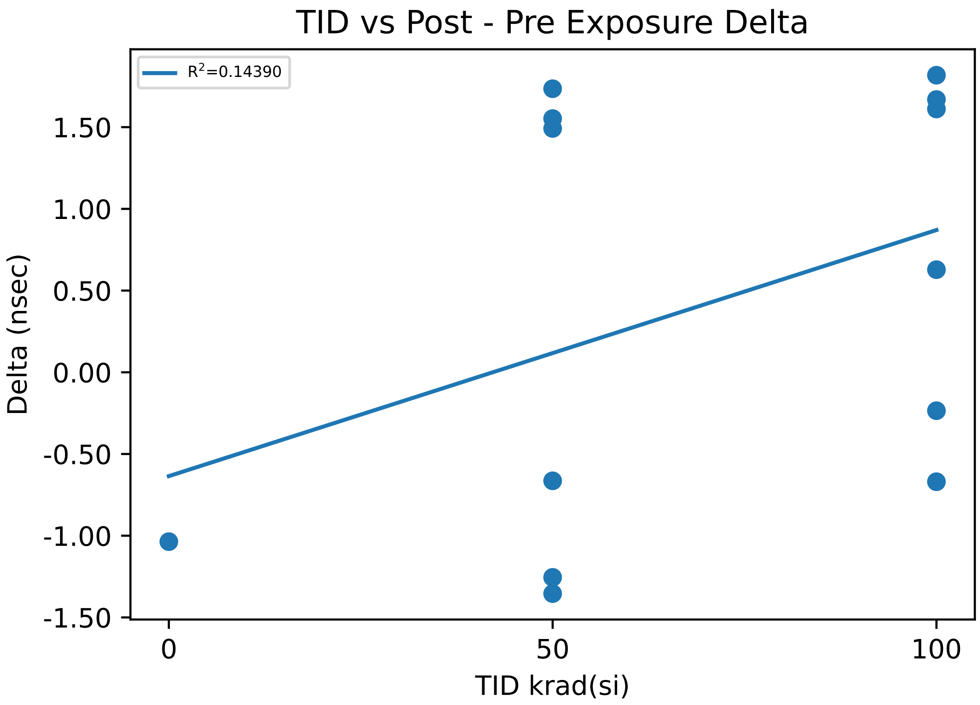
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	97.961	95.366	-2.5945
60	50	Biased	99.548	94.585	-4.9633
61	50	Biased	100.23	98.025	-2.2094
63	100	Biased	99.803	94.39	-5.4133
64	100	Biased	98.333	90.95	-7.3827
65	100	Biased	99.973	92.604	-7.3686
66	50	Unbiased	96.353	91.645	-4.7085
67	50	Unbiased	99.297	97.49	-1.8073
68	50	Unbiased	100.18	94.65	-5.5295
69	100	Unbiased	100.94	95.581	-5.3542
70	100	Unbiased	98.858	90.686	-8.171
71	100	Unbiased	97.584	93.155	-4.4297
72	0	Control	100.09	98.857	-1.2321

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100.09	100.09	100.09		98.857	98.857	98.857		-1.2321	-1.2321	-1.2321	
50	96.353	98.929	100.23	1.5073	91.645	95.294	98.025	2.3031	-5.5295	-3.6354	-1.8073	1.6101
100	97.584	99.248	100.94	1.2198	90.686	92.894	95.581	1.9112	-8.171	-6.3533	-4.4297	1.4817

Device Test: 97.24 DHL Dead Time Min 1MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

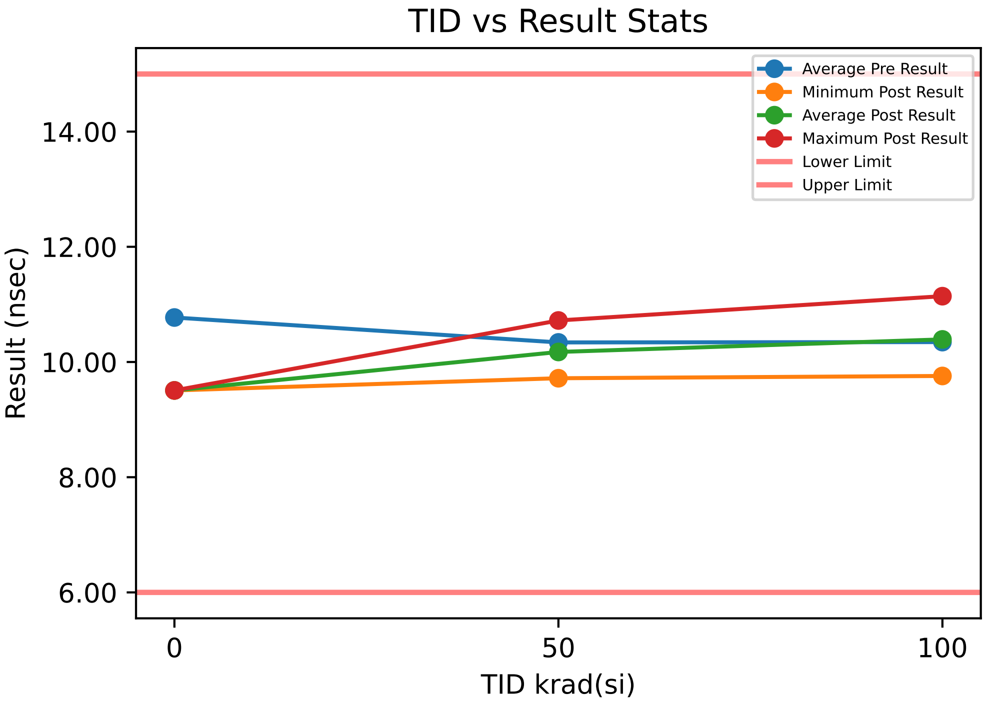
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

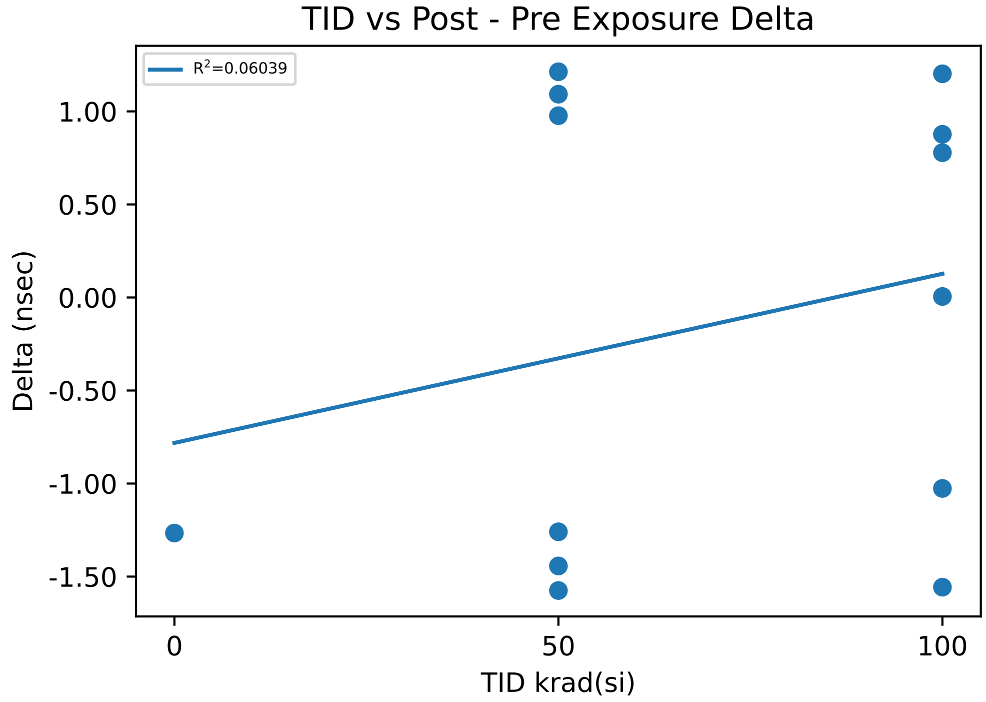
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	3.9887	5.5411	1.5524
60	50	Biased	5.4646	4.8005	-0.6641
61	50	Biased	3.4817	5.2168	1.7351
63	100	Biased	3.9638	5.633	1.6692
64	100	Biased	5.4981	5.2631	-0.235
65	100	Biased	3.9892	4.6171	0.6279
66	50	Unbiased	5.7449	4.3907	-1.3542
67	50	Unbiased	3.9404	5.4324	1.492
68	50	Unbiased	5.7626	4.5078	-1.2548
69	100	Unbiased	4.6624	6.2736	1.6112
70	100	Unbiased	6.0106	5.3409	-0.6697
71	100	Unbiased	4.0619	5.8798	1.8179
72	0	Control	5.1655	4.1292	-1.0363

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.1655	5.1655	5.1655		4.1292	4.1292	4.1292		-1.0363	-1.0363	-1.0363	
50	3.4817	4.7305	5.7626	1.0361	4.3907	4.9815	5.5411	0.48539	-1.3542	0.25107	1.7351	1.4912
100	3.9638	4.6977	6.0106	0.87297	4.6171	5.5012	6.2736	0.56944	-0.6697	0.80358	1.8179	1.0687

Device Test: 97.25 DHL Dead Time Small 1MHz VIN_14V





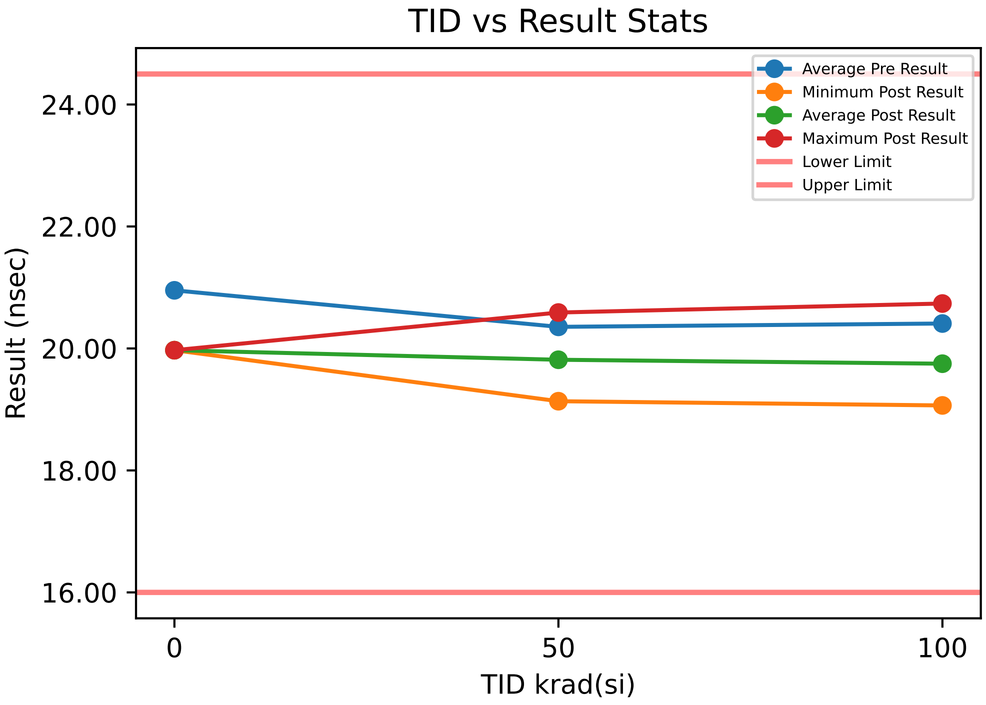
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

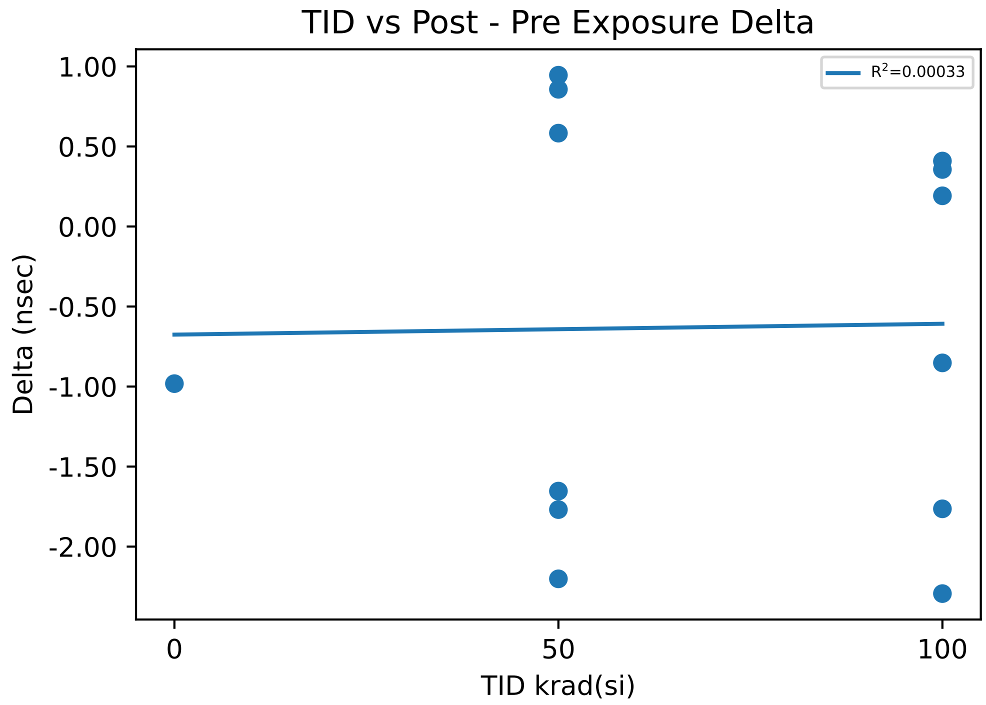
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	9.5607	10.538	0.977
60	50	Biased	10.983	9.7236	-1.2592
61	50	Biased	9.3332	10.546	1.213
63	100	Biased	9.5264	10.728	1.202
64	100	Biased	11.098	10.072	-1.0262
65	100	Biased	9.7522	9.7575	0.0053
66	50	Unbiased	11.242	9.7991	-1.4428
67	50	Unbiased	9.6284	10.721	1.0924
68	50	Unbiased	11.293	9.7181	-1.5748
69	100	Unbiased	10.364	11.143	0.7781
70	100	Unbiased	11.572	10.016	-1.5568
71	100	Unbiased	9.7603	10.637	0.8769
72	0	Control	10.772	9.5064	-1.266

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.772	10.772	10.772		9.5064	9.5064	9.5064		-1.266	-1.266	-1.266	
50	9.3332	10.34	11.293	0.92325	9.7181	10.174	10.721	0.47351	-1.5748	-0.16573	1.213	1.3858
100	9.5264	10.346	11.572	0.82915	9.7575	10.392	11.143	0.52601	-1.5568	0.04655	1.202	1.121

Device Test: 97.26 DHL Dead Time Mid 1MHz VIN_14V





Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

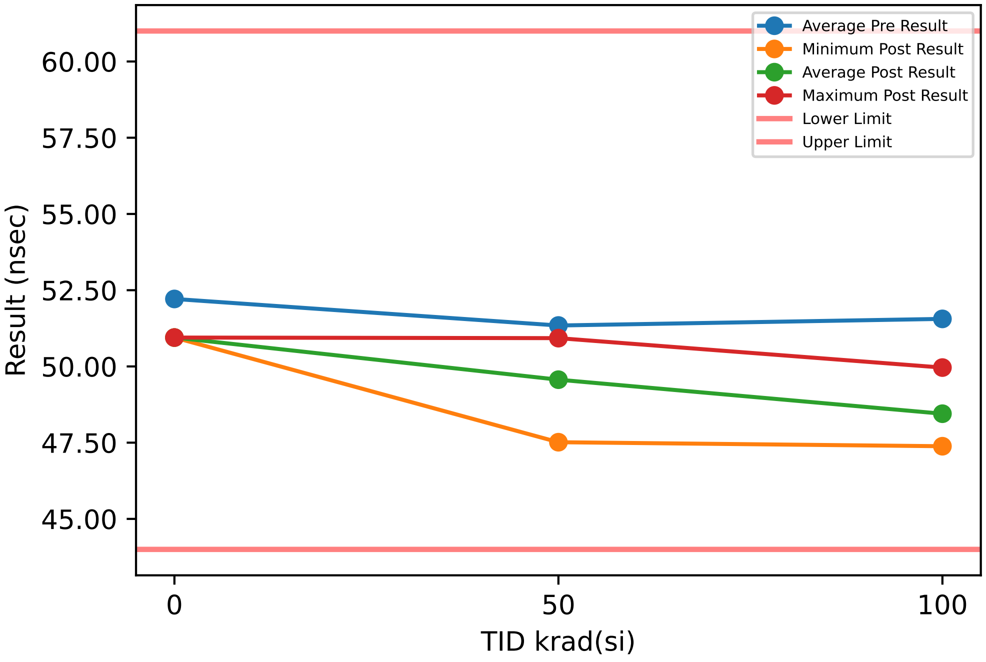
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	19.548	20.131	0.5832
60	50	Biased	20.975	19.322	-1.6532
61	50	Biased	19.561	20.506	0.9452
63	100	Biased	19.773	20.182	0.4089
64	100	Biased	20.94	19.176	-1.7639
65	100	Biased	19.918	19.066	-0.8521
66	50	Unbiased	20.903	19.135	-1.7687
67	50	Unbiased	19.732	20.589	0.8571
68	50	Unbiased	21.406	19.204	-2.2013
69	100	Unbiased	20.545	20.736	0.1917
70	100	Unbiased	21.504	19.211	-2.2935
71	100	Unbiased	19.772	20.129	0.3562
72	0	Control	20.953	19.971	-0.9818

Test Statistics (nsec)

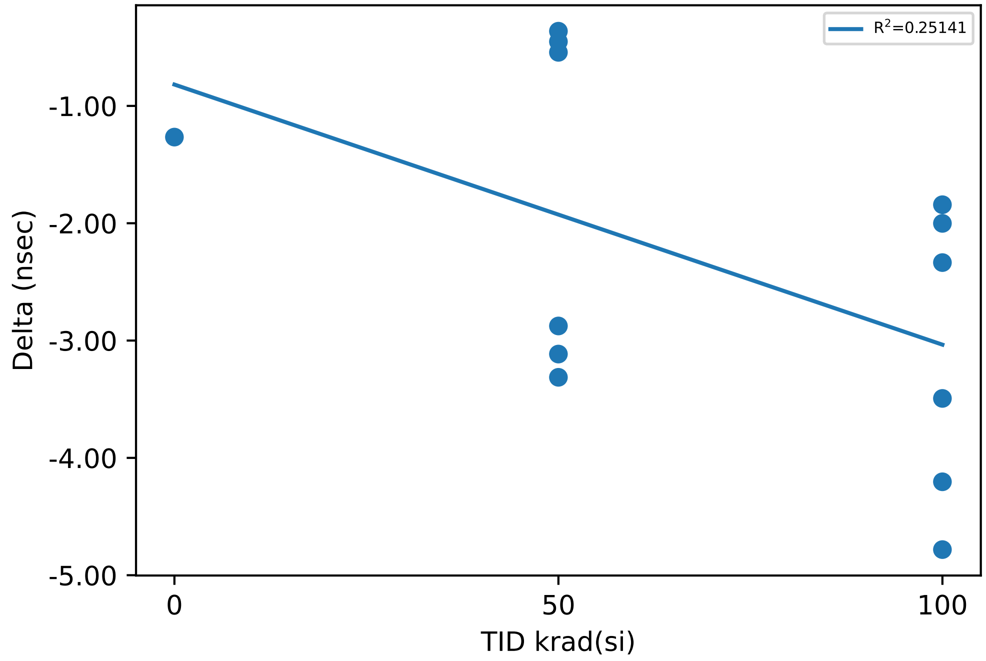
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.953	20.953	20.953		19.971	19.971	19.971		-0.9818	-0.9818	-0.9818	
50	19.548	20.354	21.406	0.83176	19.135	19.815	20.589	0.67162	-2.2013	-0.53962	0.9452	1.4784
100	19.772	20.409	21.504	0.71438	19.066	19.75	20.736	0.6915	-2.2935	-0.65878	0.4089	1.1683

Device Test: 97.27 DHL Dead Time Large 1MHz VIN_14V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



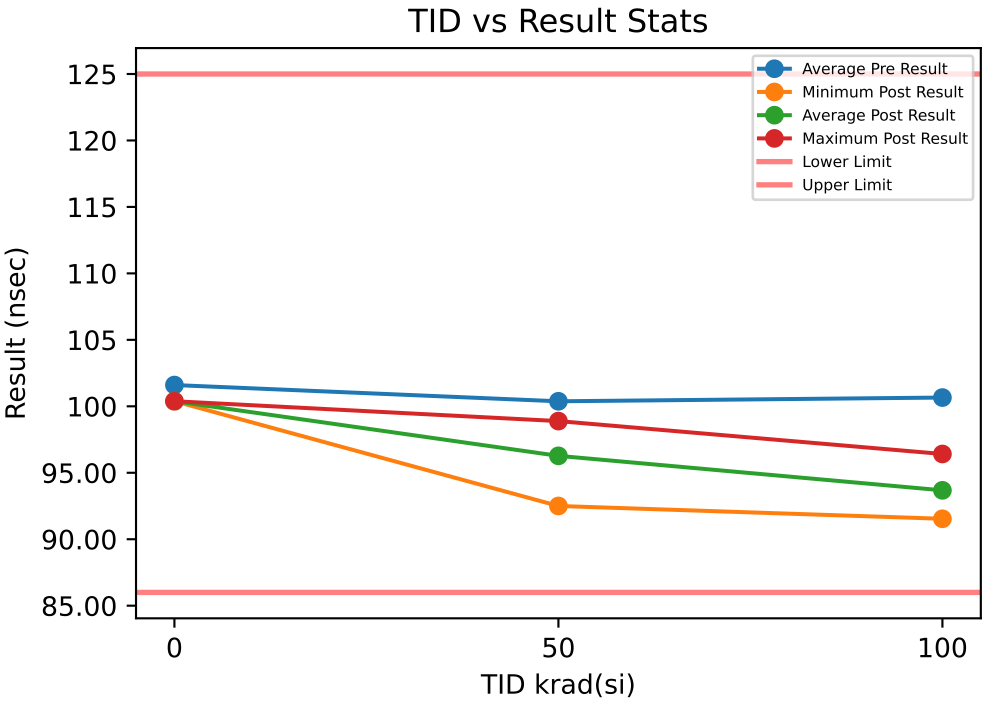
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

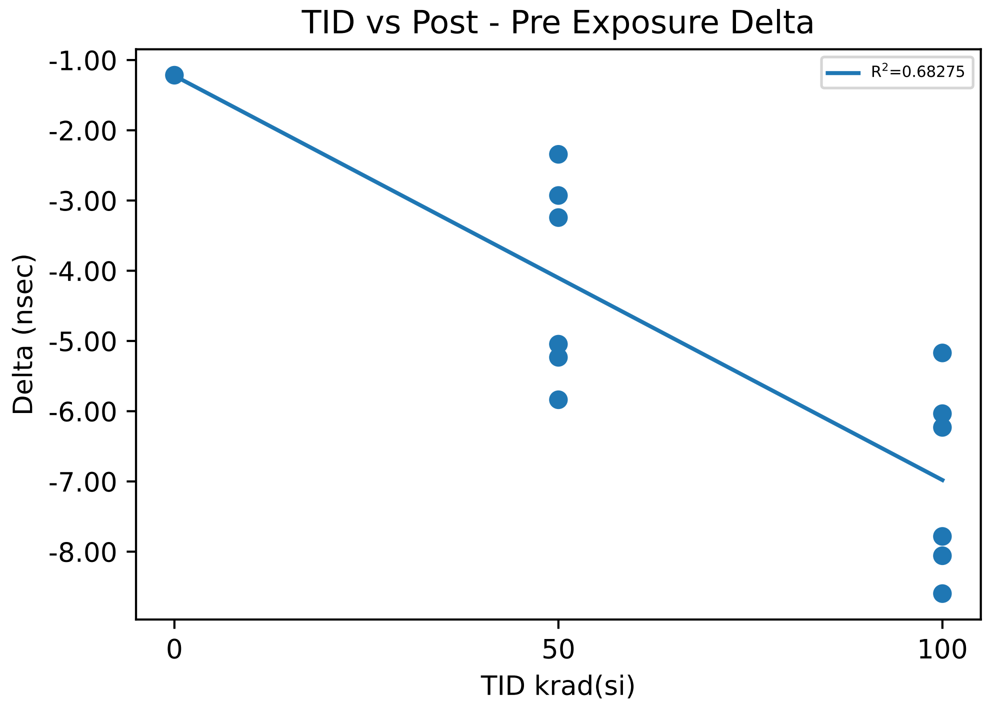
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	50.564	50.02	-0.5435
60	50	Biased	51.851	48.976	-2.8756
61	50	Biased	51.284	50.832	-0.4521
63	100	Biased	51.169	49.168	-2.0013
64	100	Biased	51.587	47.383	-4.2037
65	100	Biased	51.505	48.011	-3.4932
66	50	Unbiased	50.63	47.515	-3.1151
67	50	Unbiased	51.291	50.928	-0.3632
68	50	Unbiased	52.435	49.122	-3.3132
69	100	Unbiased	52.298	49.963	-2.3354
70	100	Unbiased	52.18	47.398	-4.7817
71	100	Unbiased	50.616	48.774	-1.8421
72	0	Control	52.213	50.947	-1.2658

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.213	52.213	52.213		50.947	50.947	50.947		-1.2658	-1.2658	-1.2658	
50	50.564	51.342	52.435	0.71725	47.515	49.565	50.928	1.2974	-3.3132	-1.7771	-0.3632	1.4583
100	50.616	51.559	52.298	0.62883	47.383	48.45	49.963	1.0339	-4.7817	-3.1096	-1.8421	1.2308

Device Test: 97.28 DHL Dead Time Max 1MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

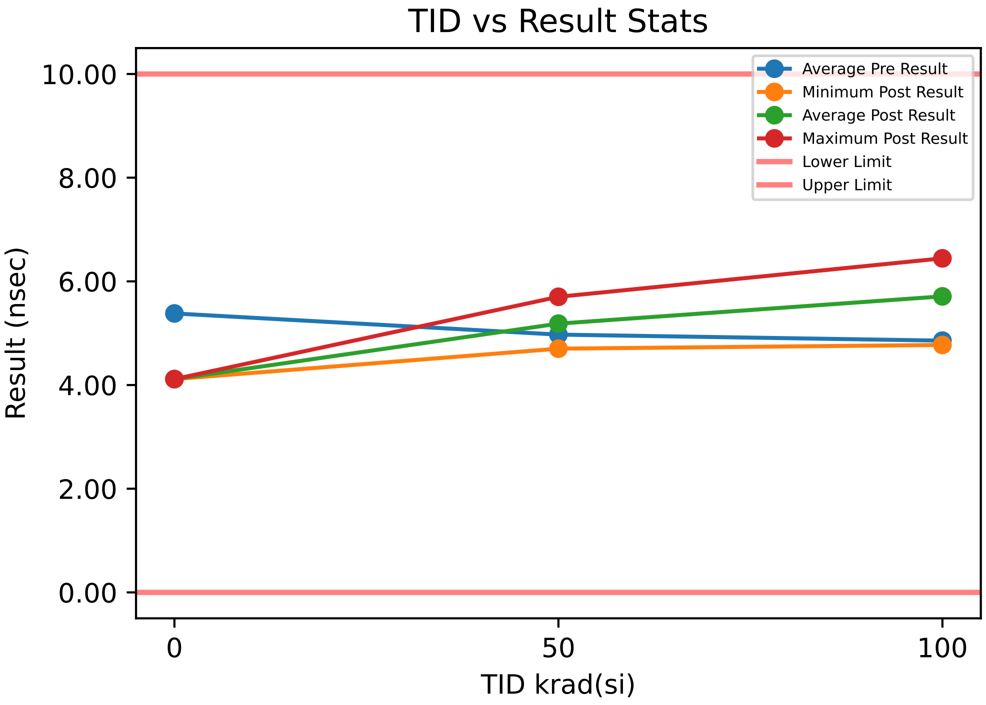
Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

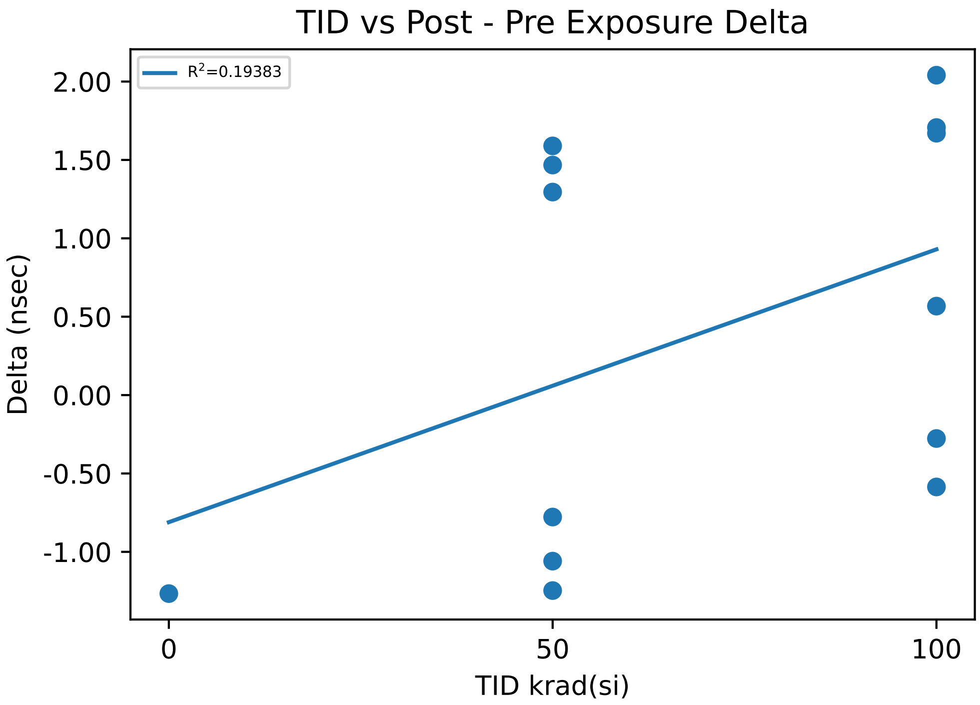
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	99.545	96.302	-3.243
60	50	Biased	100.93	95.693	-5.2329
61	50	Biased	101.82	98.888	-2.9284
63	100	Biased	101.32	95.086	-6.2305
64	100	Biased	99.697	91.639	-8.058
65	100	Biased	101.46	93.674	-7.7827
66	50	Unbiased	97.548	92.502	-5.0456
67	50	Unbiased	100.84	98.497	-2.3423
68	50	Unbiased	101.59	95.755	-5.8369
69	100	Unbiased	102.45	96.414	-6.0348
70	100	Unbiased	100.14	91.539	-8.597
71	100	Unbiased	98.894	93.723	-5.1703
72	0	Control	101.6	100.38	-1.2157

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	101.6	101.6	101.6		100.38	100.38	100.38		-1.2157	-1.2157	-1.2157	
50	97.548	100.38	101.82	1.5974	92.502	96.273	98.888	2.3069	-5.8369	-4.1049	-2.3423	1.4416
100	98.894	100.66	102.45	1.3106	91.539	93.679	96.414	1.9082	-8.597	-6.9789	-5.1703	1.3529

Device Test: 97.29 DHL Dead Time Min 2MHz VIN_14V





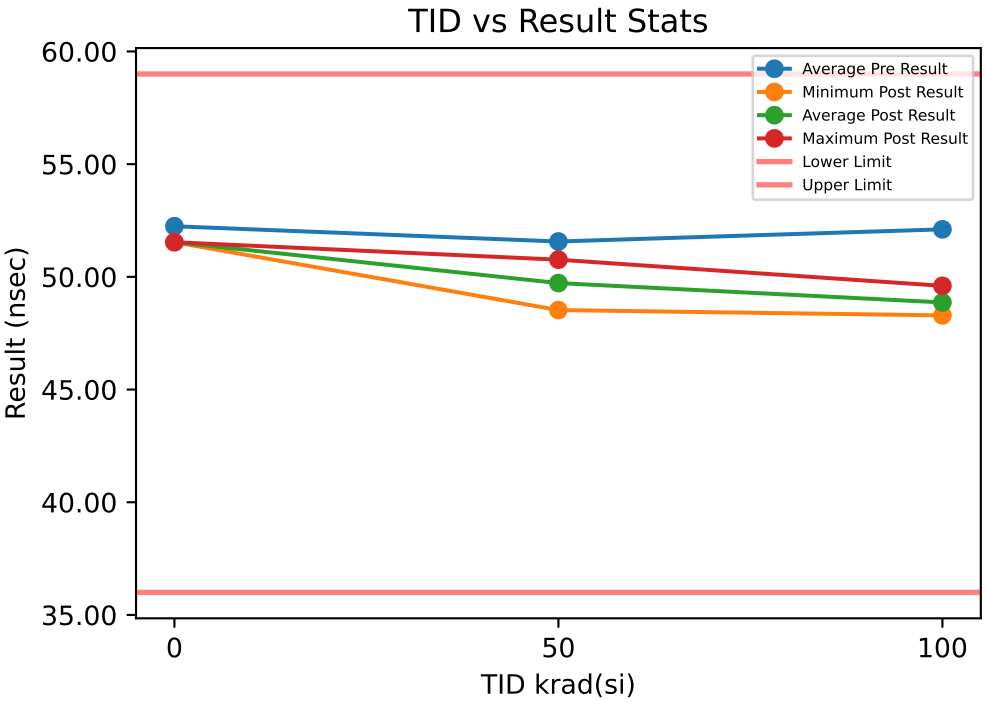
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

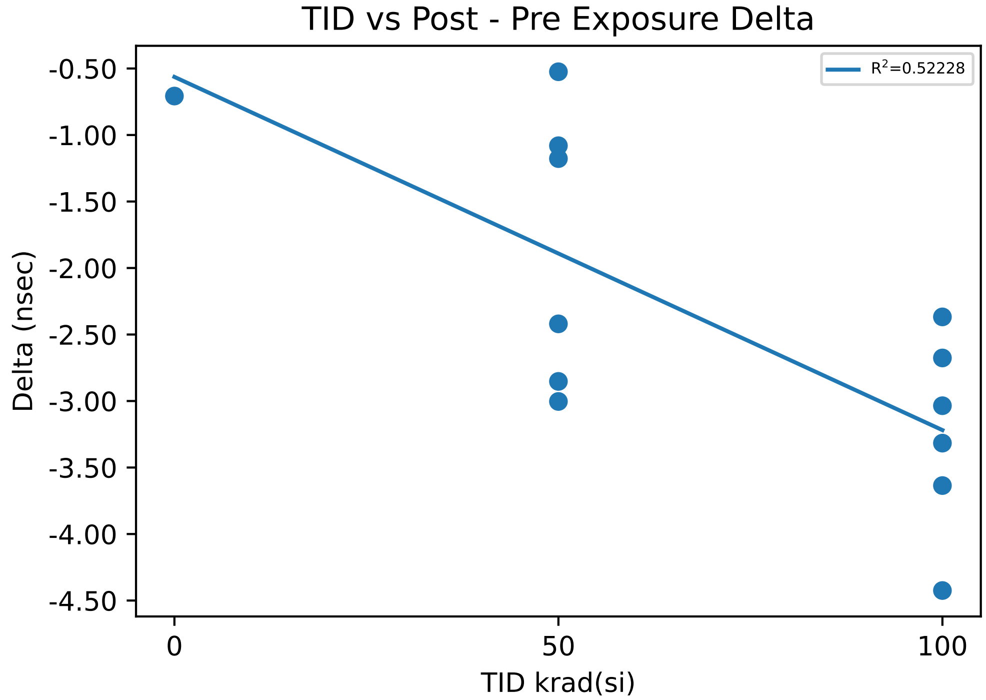
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.2388	5.534	1.2952
60	50	Biased	5.6887	4.9108	-0.7779
61	50	Biased	3.8912	5.3587	1.4675
63	100	Biased	4.0858	6.1264	2.0406
64	100	Biased	5.7602	5.4832	-0.277
65	100	Biased	4.2057	4.7733	0.5676
66	50	Unbiased	5.9581	4.8989	-1.0592
67	50	Unbiased	4.1125	5.7021	1.5896
68	50	Unbiased	5.9486	4.7016	-1.247
69	100	Unbiased	4.7734	6.4439	1.6705
70	100	Unbiased	6.0833	5.4973	-0.586
71	100	Unbiased	4.2306	5.9374	1.7068
72	0	Control	5.3809	4.1146	-1.2663

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.3809	5.3809	5.3809		4.1146	4.1146	4.1146		-1.2663	-1.2663	-1.2663	
50	3.8912	4.973	5.9581	0.98836	4.7016	5.1843	5.7021	0.40251	-1.247	0.21137	1.5896	1.3691
100	4.0858	4.8565	6.0833	0.86463	4.7733	5.7102	6.4439	0.58954	-0.586	0.85375	2.0406	1.1168

Device Test: 97.3 DLH Dead Time Large 500kHz VIN_14V





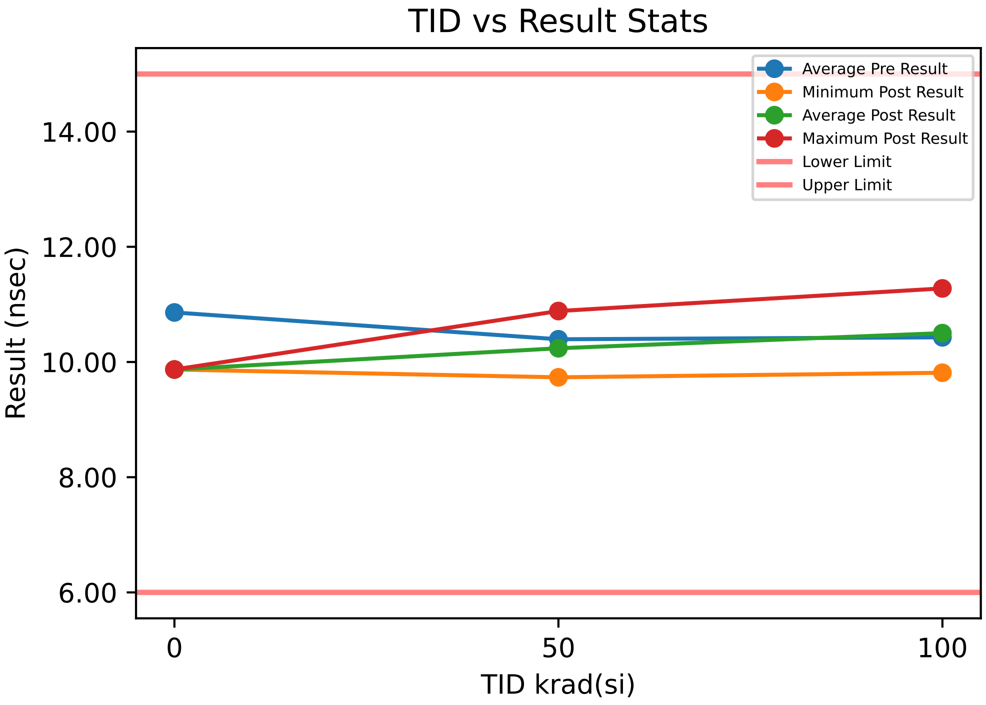
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

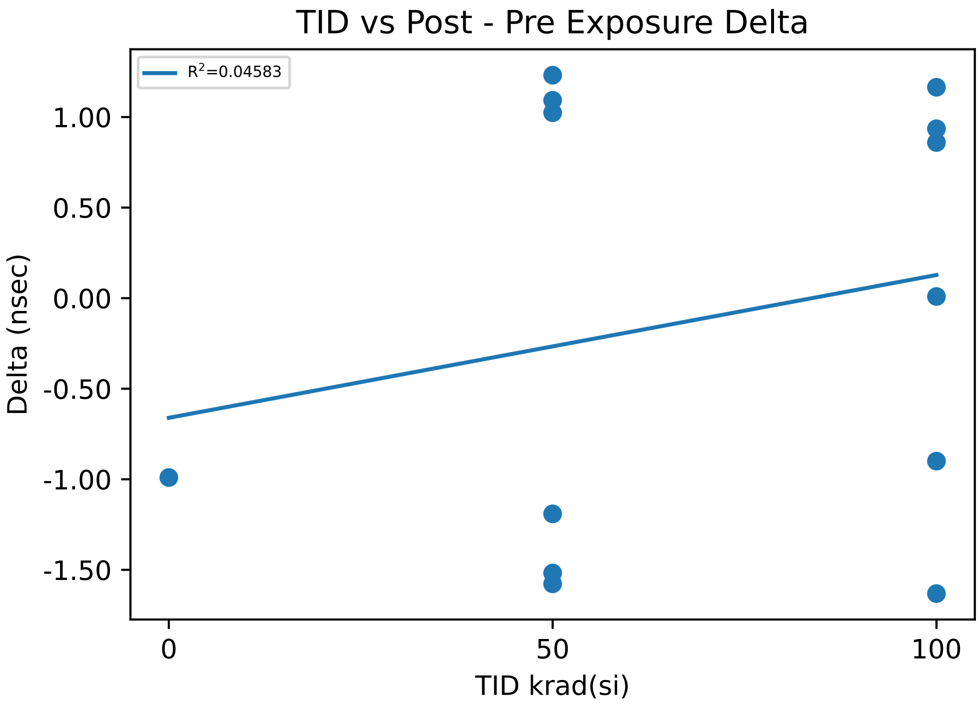
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	51.286	50.762	-0.5245
60	50	Biased	51.529	48.526	-3.0033
61	50	Biased	51.251	50.073	-1.1775
63	100	Biased	50.912	48.544	-2.3675
64	100	Biased	51.869	48.553	-3.3166
65	100	Biased	52.781	49.145	-3.6356
66	50	Unbiased	52.033	49.18	-2.8525
67	50	Unbiased	51.297	50.216	-1.0806
68	50	Unbiased	52.012	49.592	-2.4198
69	100	Unbiased	52.637	49.601	-3.0352
70	100	Unbiased	52.715	48.29	-4.4247
71	100	Unbiased	51.734	49.058	-2.6762
72	0	Control	52.244	51.537	-0.7072

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.244	52.244	52.244		51.537	51.537	51.537		-0.7072	-0.7072	-0.7072	
50	51.251	51.568	52.033	0.36553	48.526	49.725	50.762	0.79859	-3.0033	-1.843	-0.5245	1.0451
100	50.912	52.108	52.781	0.73871	48.29	48.865	49.601	0.48757	-4.4247	-3.2426	-2.3675	0.73306

Device Test: 97.30 DHL Dead Time Small 2MHz VIN_14V





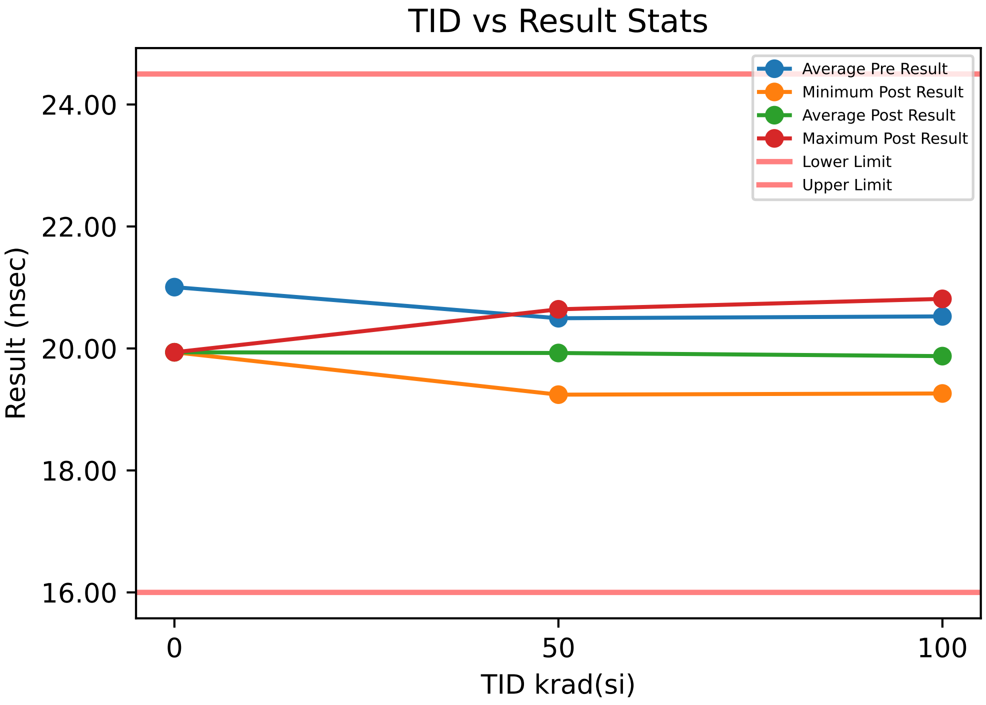
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

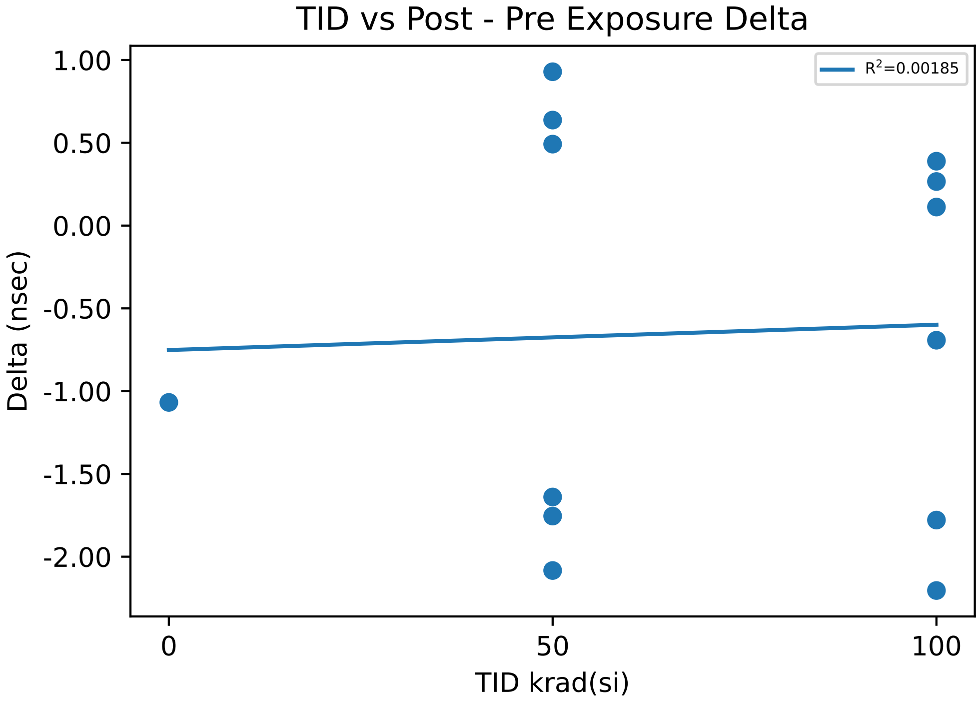
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	9.5671	10.591	1.0238
60	50	Biased	11.098	9.907	-1.1909
61	50	Biased	9.3054	10.537	1.2311
63	100	Biased	9.627	10.791	1.1645
64	100	Biased	11.067	10.167	-0.8998
65	100	Biased	9.8039	9.8131	0.0092
66	50	Unbiased	11.312	9.7341	-1.5774
67	50	Unbiased	9.7922	10.885	1.0925
68	50	Unbiased	11.295	9.7769	-1.5177
69	100	Unbiased	10.418	11.277	0.8594
70	100	Unbiased	11.71	10.079	-1.6312
71	100	Unbiased	9.9446	10.88	0.9354
72	0	Control	10.86	9.8698	-0.9903

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.86	10.86	10.86		9.8698	9.8698	9.8698		-0.9903	-0.9903	-0.9903	
50	9.3054	10.395	11.312	0.93588	9.7341	10.238	10.885	0.49152	-1.5774	-0.15643	1.2311	1.4015
100	9.627	10.428	11.71	0.81433	9.8131	10.501	11.277	0.56467	-1.6312	0.072917	1.1645	1.1321

Device Test: 97.31 DHL Dead Time Mid 2MHz VIN_14V





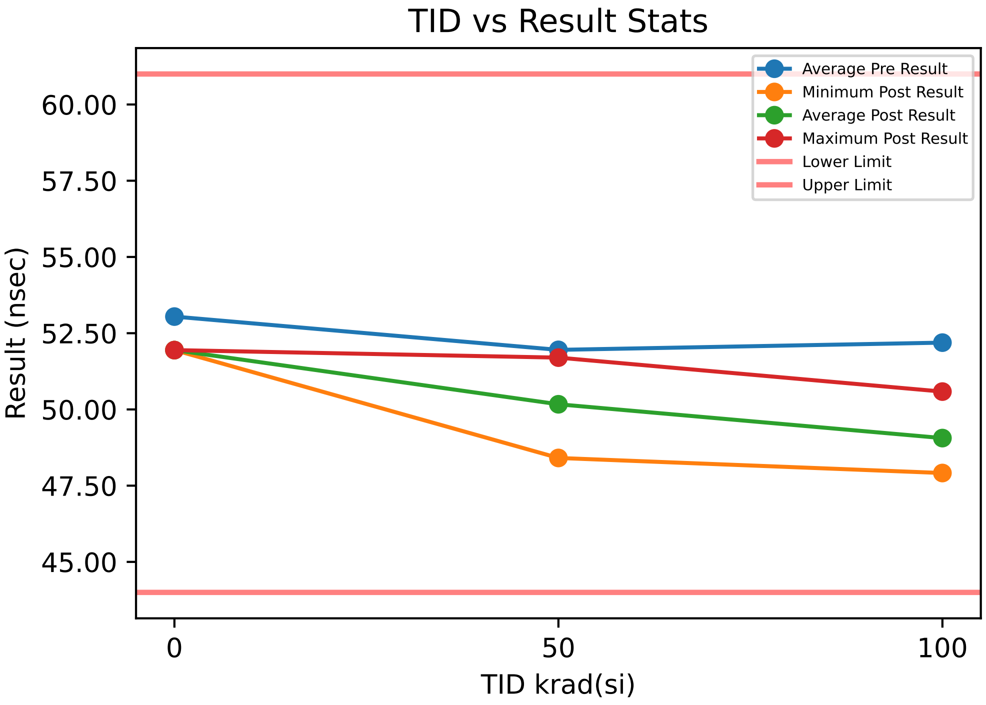
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

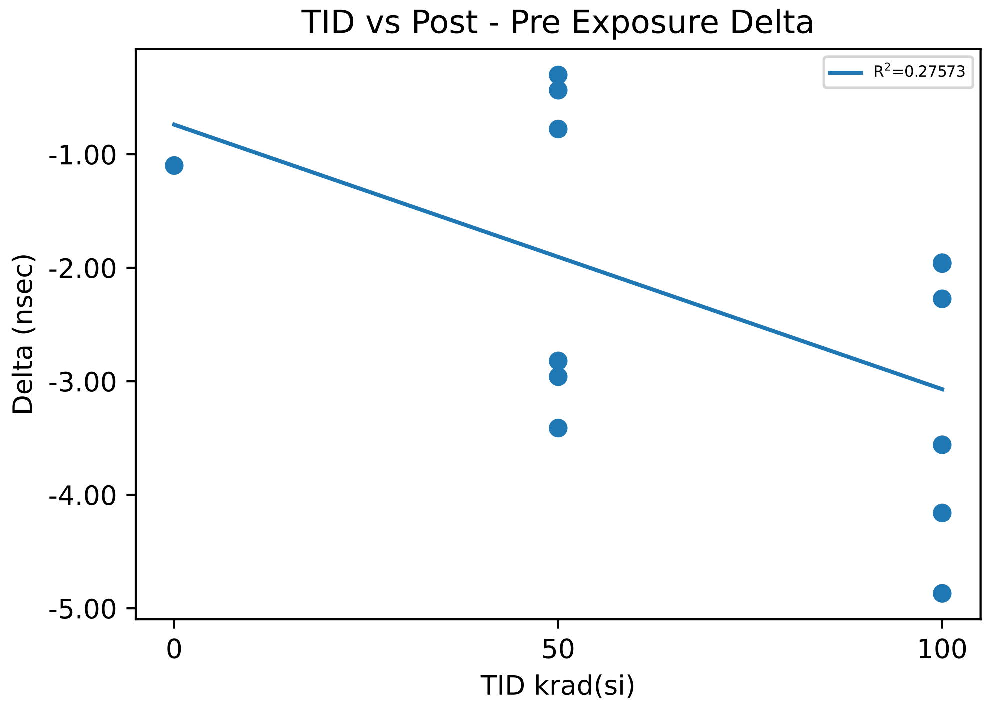
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	19.683	20.175	0.492
60	50	Biased	21.09	19.451	-1.6394
61	50	Biased	19.676	20.605	0.9292
63	100	Biased	19.888	20.277	0.3888
64	100	Biased	21.041	19.262	-1.7788
65	100	Biased	20.056	19.364	-0.6925
66	50	Unbiased	20.997	19.242	-1.7545
67	50	Unbiased	20.005	20.642	0.6373
68	50	Unbiased	21.521	19.438	-2.0835
69	100	Unbiased	20.701	20.813	0.112
70	100	Unbiased	21.567	19.363	-2.2043
71	100	Unbiased	19.9	20.166	0.2662
72	0	Control	21.005	19.937	-1.0681

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.005	21.005	21.005		19.937	19.937	19.937		-1.0681	-1.0681	-1.0681	
50	19.676	20.495	21.521	0.80369	19.242	19.925	20.642	0.62729	-2.0835	-0.56982	0.9292	1.3907
100	19.888	20.526	21.567	0.69256	19.262	19.874	20.813	0.63656	-2.2043	-0.65143	0.3888	1.1127

Device Test: 97.32 DHL Dead Time Large 2MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

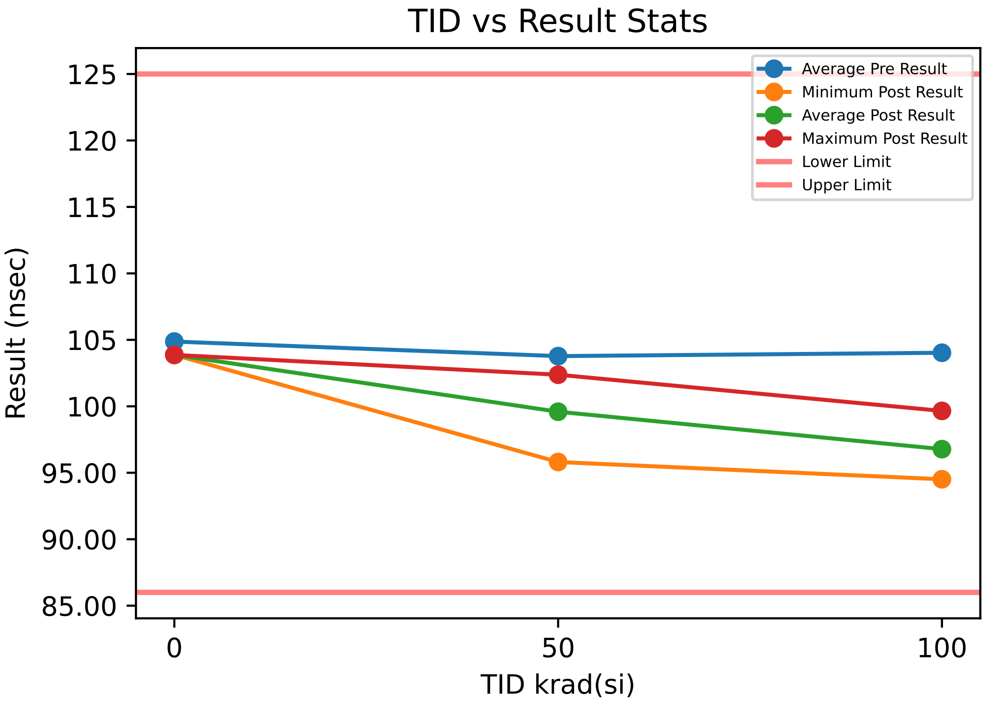
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

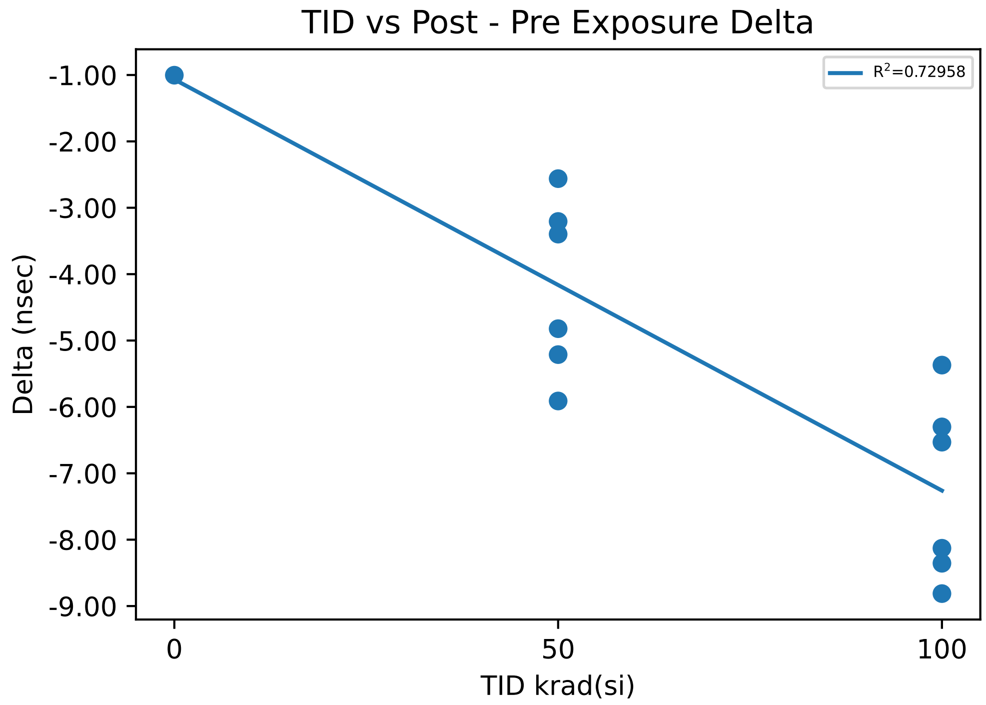
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	51.266	50.488	-0.7774
60	50	Biased	52.339	49.38	-2.9595
61	50	Biased	52.001	51.699	-0.3014
63	100	Biased	51.895	49.932	-1.9631
64	100	Biased	52.164	48.005	-4.1598
65	100	Biased	52.269	48.709	-3.5593
66	50	Unbiased	51.229	48.409	-2.8204
67	50	Unbiased	51.83	51.394	-0.4355
68	50	Unbiased	53.057	49.645	-3.412
69	100	Unbiased	52.859	50.585	-2.2736
70	100	Unbiased	52.783	47.915	-4.8683
71	100	Unbiased	51.173	49.218	-1.9555
72	0	Control	53.045	51.946	-1.0991

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	53.045	53.045	53.045		51.946	51.946	51.946		-1.0991	-1.0991	-1.0991	
50	51.229	51.953	53.057	0.69006	48.409	50.169	51.699	1.2602	-3.412	-1.7844	-0.3014	1.4238
100	51.173	52.191	52.859	0.62079	47.915	49.061	50.585	1.0638	-4.8683	-3.1299	-1.9555	1.2443

Device Test: 97.33 DHL Dead Time Max 2MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

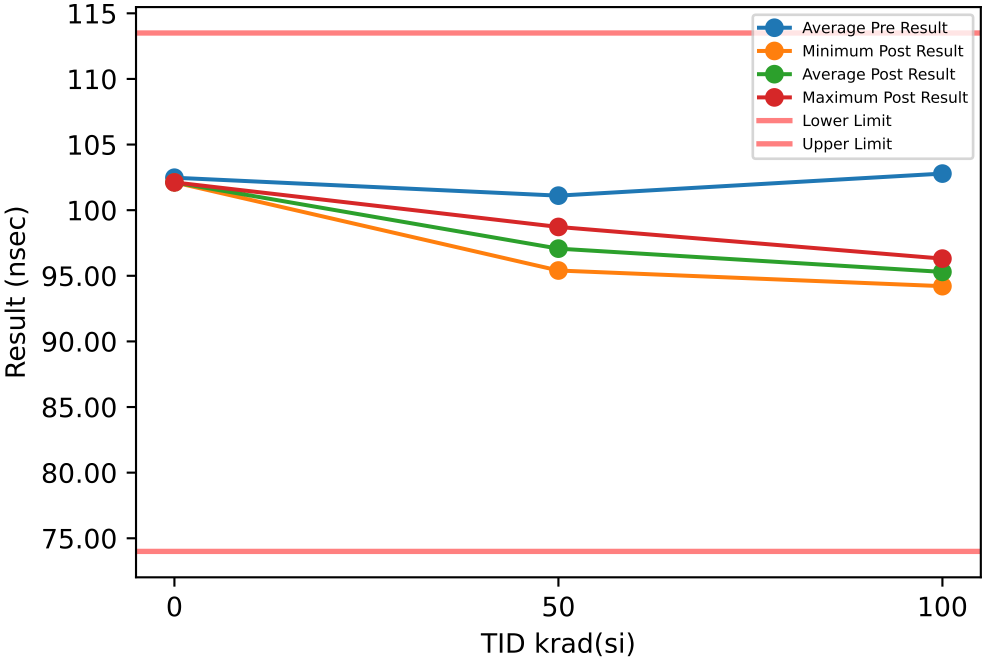
Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

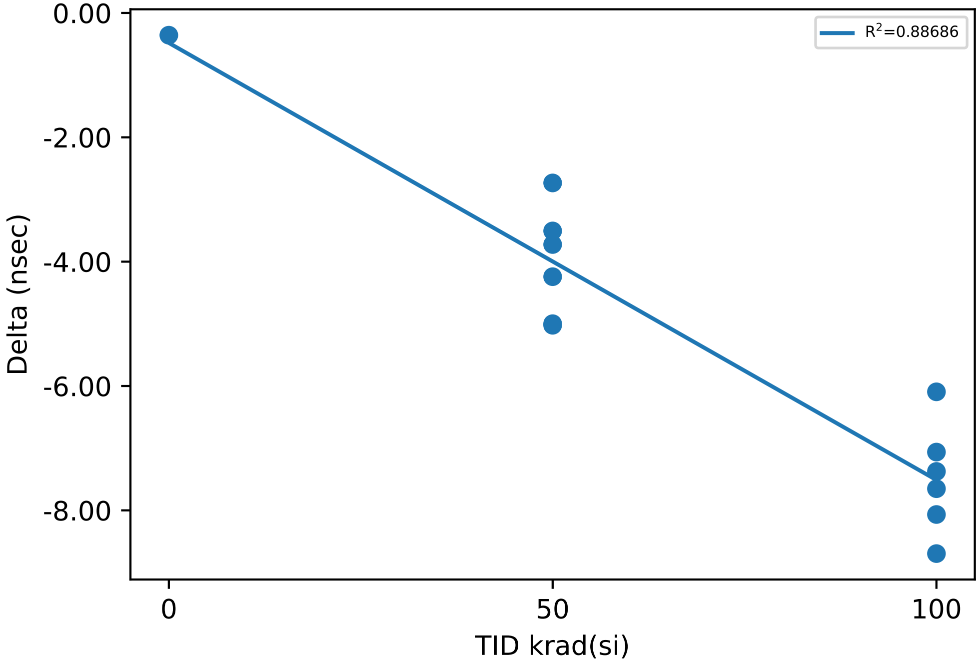
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	102.87	99.474	-3.3969
60	50	Biased	104.31	99.097	-5.2121
61	50	Biased	105.58	102.38	-3.2065
63	100	Biased	104.9	98.365	-6.531
64	100	Biased	103.02	94.667	-8.3554
65	100	Biased	104.76	96.634	-8.1291
66	50	Unbiased	100.63	95.81	-4.8216
67	50	Unbiased	104.26	101.69	-2.5614
68	50	Unbiased	105.01	99.097	-5.9107
69	100	Unbiased	105.95	99.654	-6.3011
70	100	Unbiased	103.32	94.511	-8.8123
71	100	Unbiased	102.21	96.838	-5.3701
72	0	Control	104.87	103.87	-1.003

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	104.87	104.87	104.87		103.87	103.87	103.87		-1.003	-1.003	-1.003	
50	100.63	103.78	105.58	1.789	95.81	99.591	102.38	2.323	-5.9107	-4.1849	-2.5614	1.3155
100	102.21	104.03	105.95	1.4021	94.511	96.778	99.654	2.0206	-8.8123	-7.2498	-5.3701	1.3702

Device Test: 97.4 DLH Dead Time Max 500kHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

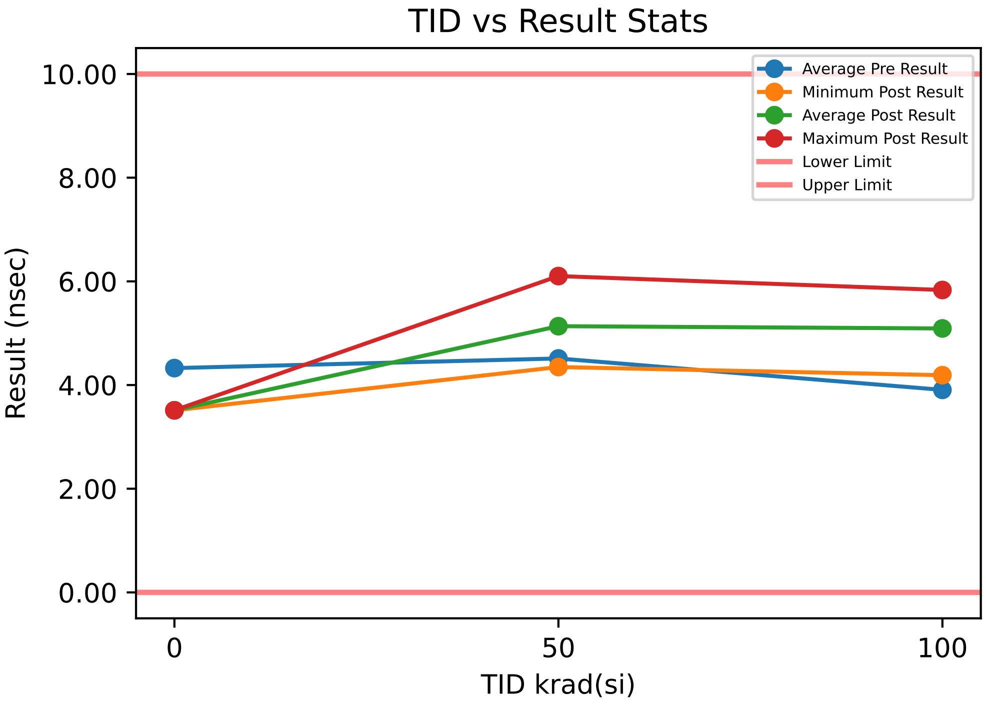
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

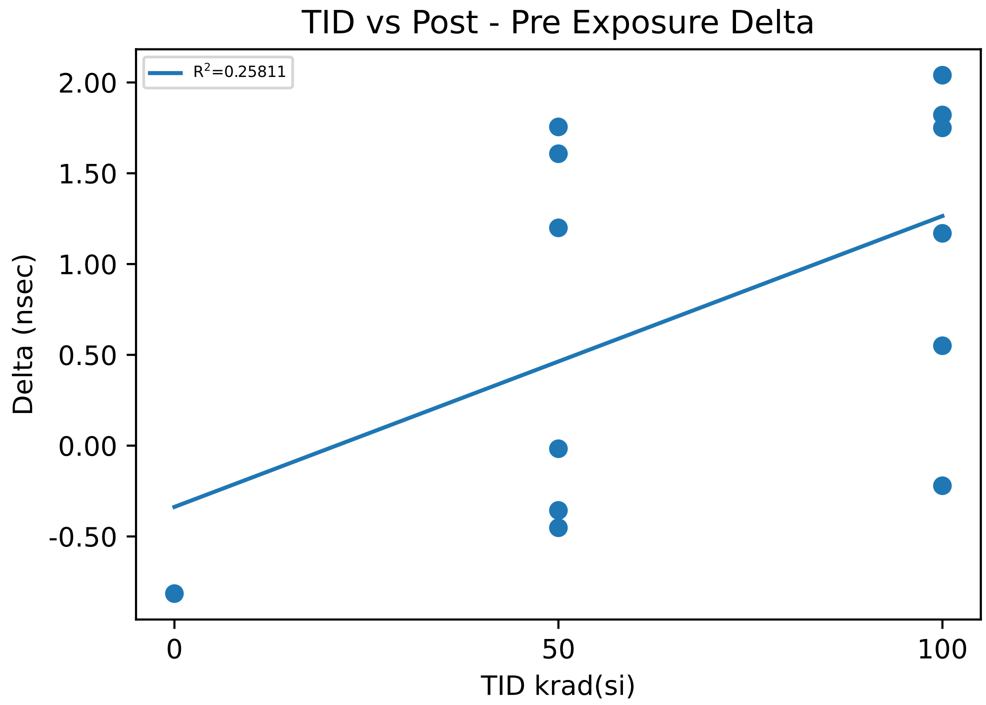
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	101.46	98.722	-2.7337
60	50	Biased	100.4	95.403	-4.9977
61	50	Biased	100.67	96.942	-3.7241
63	100	Biased	100.68	94.582	-6.0935
64	100	Biased	101.58	94.21	-7.3741
65	100	Biased	103.96	96.309	-7.6517
66	50	Unbiased	101.26	96.239	-5.023
67	50	Unbiased	101.24	97.737	-3.506
68	50	Unbiased	101.62	97.374	-4.2417
69	100	Unbiased	103.66	95.593	-8.0667
70	100	Unbiased	103.63	94.939	-8.6955
71	100	Unbiased	103.21	96.146	-7.0627
72	0	Control	102.47	102.12	-0.3575

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	102.47	102.47	102.47		102.12	102.12	102.12		-0.3575	-0.3575	-0.3575	
50	100.4	101.11	101.62	0.47252	95.403	97.069	98.722	1.1622	-5.023	-4.0377	-2.7337	0.89616
100	100.68	102.79	103.96	1.3371	94.21	95.297	96.309	0.85478	-8.6955	-7.4907	-6.0935	0.88974

Device Test: 97.5 DLH Dead Time Min 1MHz VIN_14V





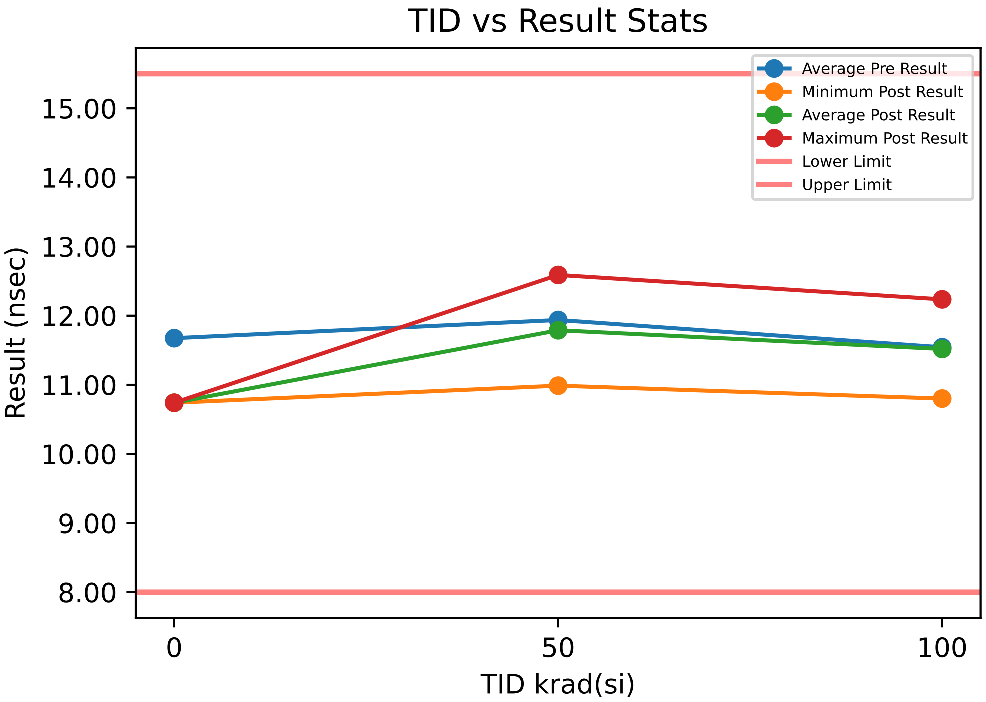
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

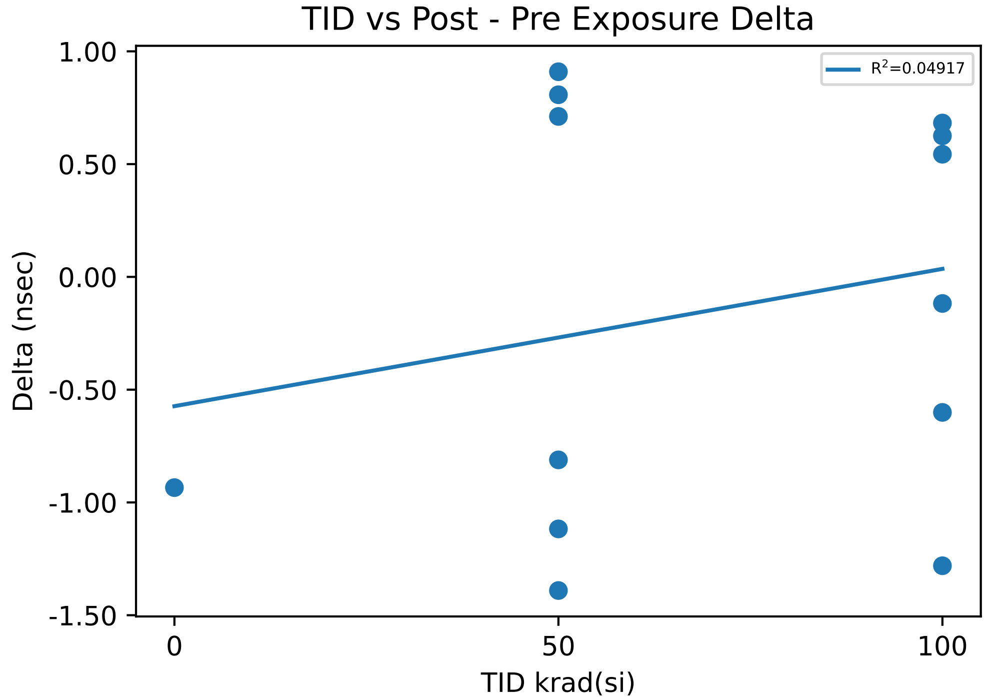
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	4.3468	6.102	1.7552
60	50	Biased	5.1407	4.6886	-0.4521
61	50	Biased	4.6468	5.8461	1.1993
63	100	Biased	4.0125	5.8335	1.821
64	100	Biased	4.555	5.7241	1.1691
65	100	Biased	3.7534	4.3036	0.5502
66	50	Unbiased	4.704	4.3474	-0.3566
67	50	Unbiased	3.4381	5.0456	1.6075
68	50	Unbiased	4.799	4.782	-0.017
69	100	Unbiased	3.8758	5.6259	1.7501
70	100	Unbiased	4.4108	4.19	-0.2208
71	100	Unbiased	2.8331	4.8731	2.04
72	0	Control	4.3269	3.5122	-0.8147

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3269	4.3269	4.3269		3.5122	3.5122	3.5122		-0.8147	-0.8147	-0.8147	
50	3.4381	4.5126	5.1407	0.58536	4.3474	5.1353	6.102	0.6918	-0.4521	0.62272	1.7552	1.0108
100	2.8331	3.9068	4.555	0.61036	4.19	5.0917	5.8335	0.73723	-0.2208	1.1849	2.04	0.87571

Device Test: 97.6 DLH Dead Time Small 1MHz VIN_14V





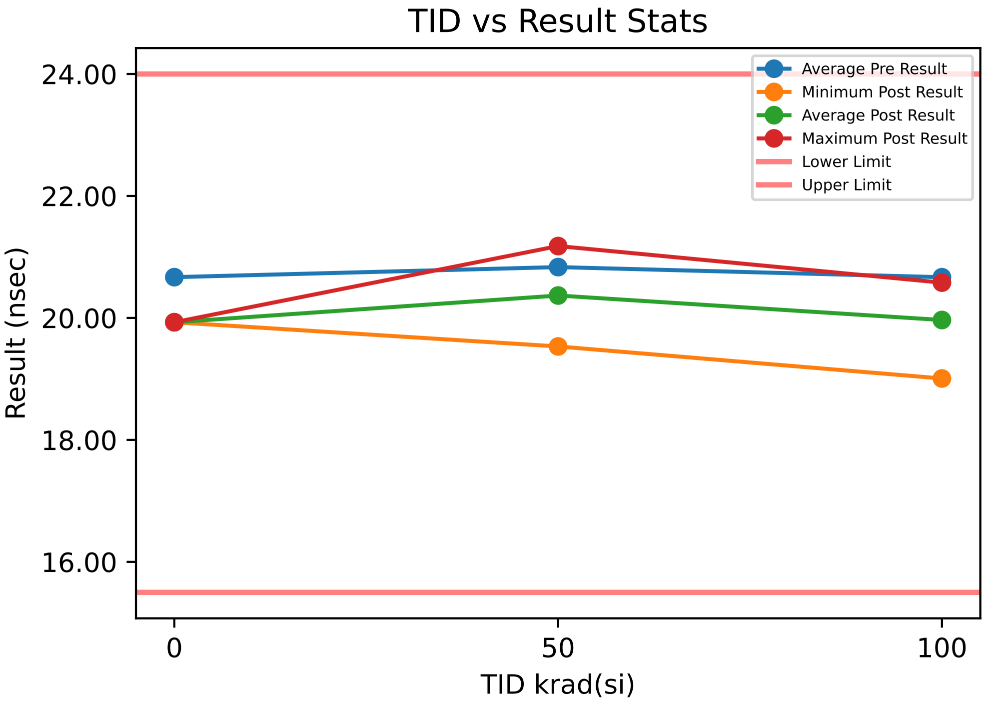
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

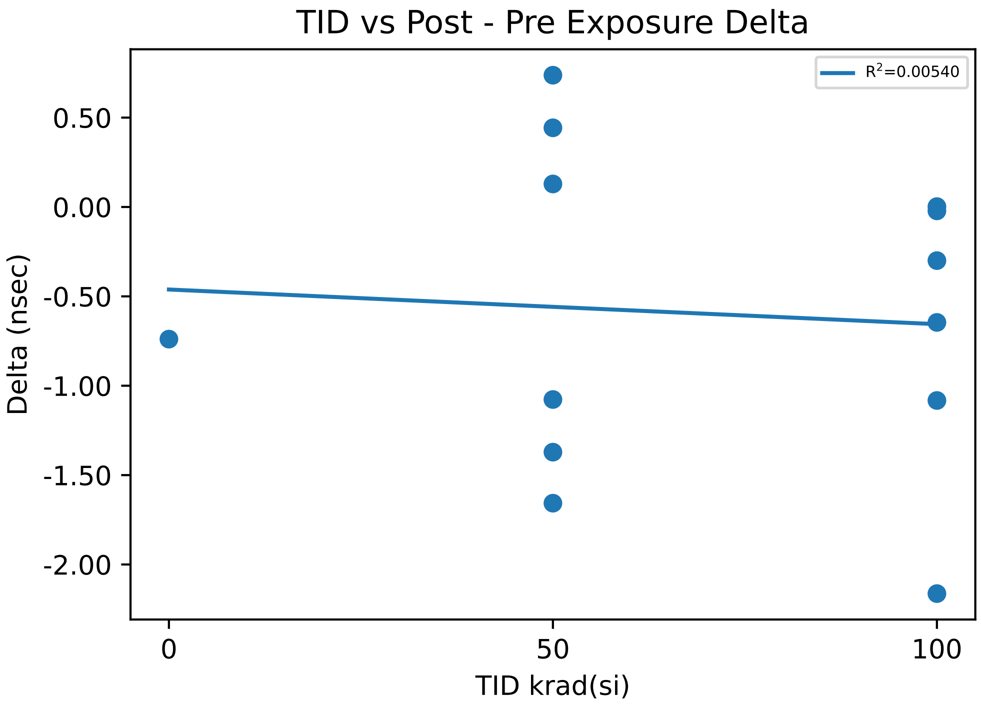
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	11.68	12.589	0.9095
60	50	Biased	12.378	10.987	-1.3905
61	50	Biased	11.84	12.552	0.7114
63	100	Biased	11.438	12.12	0.6822
64	100	Biased	11.982	11.864	-0.1178
65	100	Biased	11.576	10.976	-0.6008
66	50	Unbiased	12.249	11.132	-1.1173
67	50	Unbiased	11.084	11.891	0.8075
68	50	Unbiased	12.395	11.583	-0.8113
69	100	Unbiased	11.611	12.236	0.6254
70	100	Unbiased	12.081	10.801	-1.2806
71	100	Unbiased	10.571	11.115	0.5438
72	0	Control	11.675	10.74	-0.9343

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.675	11.675	11.675		10.74	10.74	10.74		-0.9343	-0.9343	-0.9343	
50	11.084	11.937	12.395	0.51082	10.987	11.789	12.589	0.68544	-1.3905	-0.14845	0.9095	1.0671
100	10.571	11.543	12.081	0.53736	10.801	11.519	12.236	0.6276	-1.2806	-0.024633	0.6822	0.79541

Device Test: 97.7 DLH Dead Time Mid 1MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

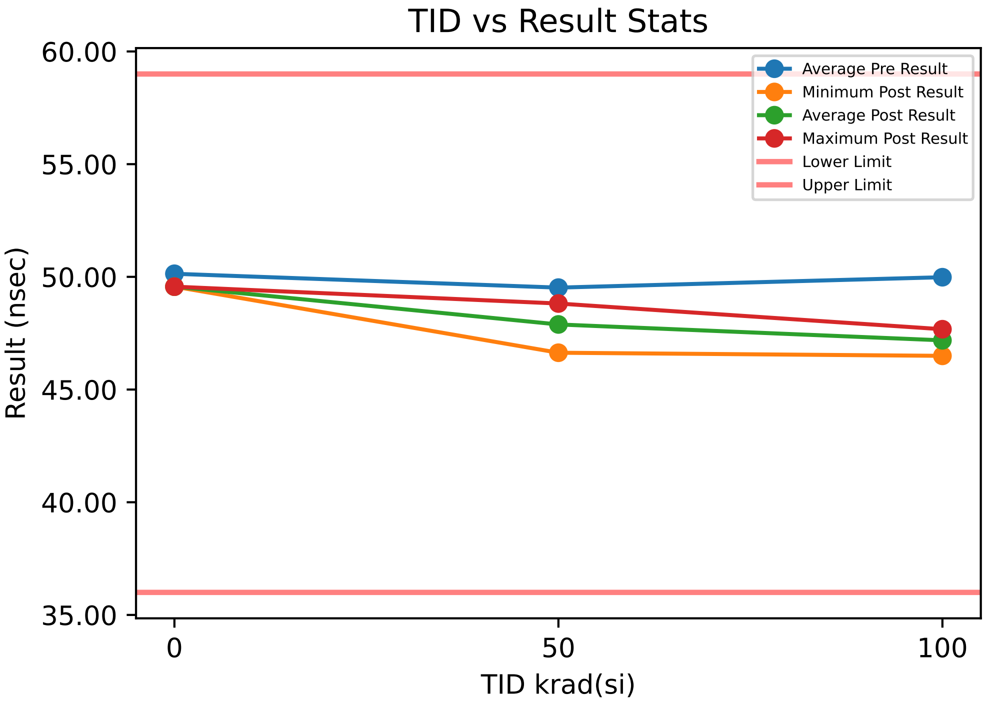
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

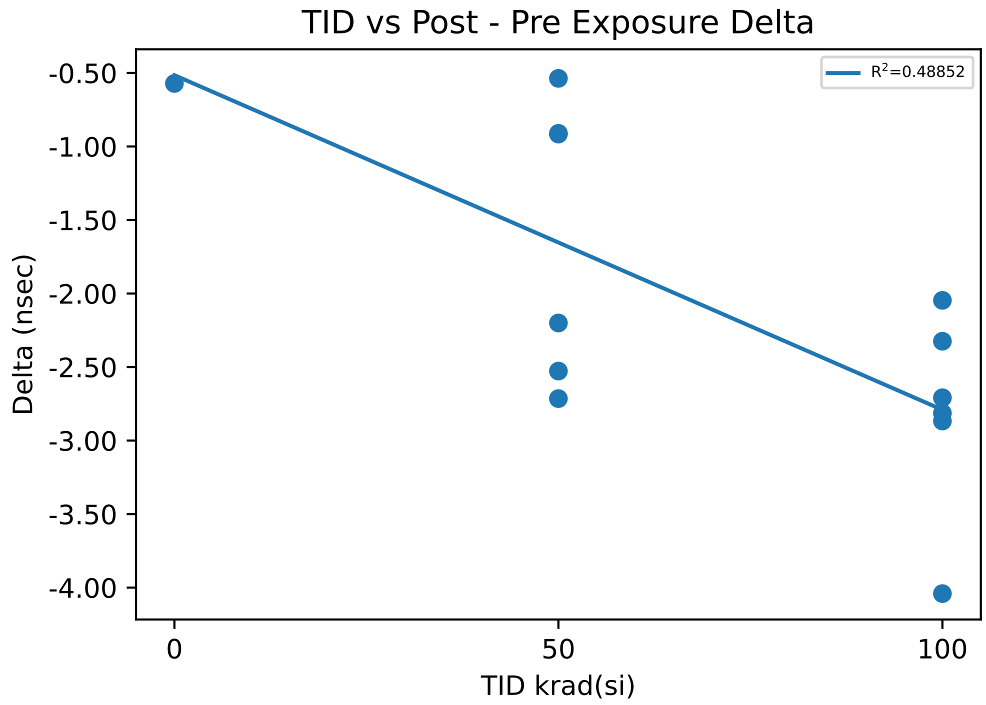
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	20.441	21.179	0.7373
60	50	Biased	21.19	19.533	-1.6571
61	50	Biased	20.78	20.909	0.1288
63	100	Biased	20.394	20.396	0.0021
64	100	Biased	20.93	20.284	-0.6458
65	100	Biased	20.849	19.766	-1.0825
66	50	Unbiased	21.171	19.799	-1.3716
67	50	Unbiased	20.162	20.605	0.443
68	50	Unbiased	21.259	20.182	-1.0771
69	100	Unbiased	20.879	20.579	-0.3
70	100	Unbiased	21.17	19.008	-2.1629
71	100	Unbiased	19.786	19.764	-0.0217
72	0	Control	20.669	19.93	-0.7392

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.669	20.669	20.669		19.93	19.93	19.93		-0.7392	-0.7392	-0.7392	
50	20.162	20.834	21.259	0.4536	19.533	20.368	21.179	0.64217	-1.6571	-0.46612	0.7373	1.0237
100	19.786	20.668	21.17	0.50018	19.008	19.966	20.579	0.57648	-2.1629	-0.7018	0.0021	0.8249

Device Test: 97.8 DLH Dead Time Large 1MHz VIN_14V


TID vs Result Stats


TID vs Post - Pre Exposure Delta

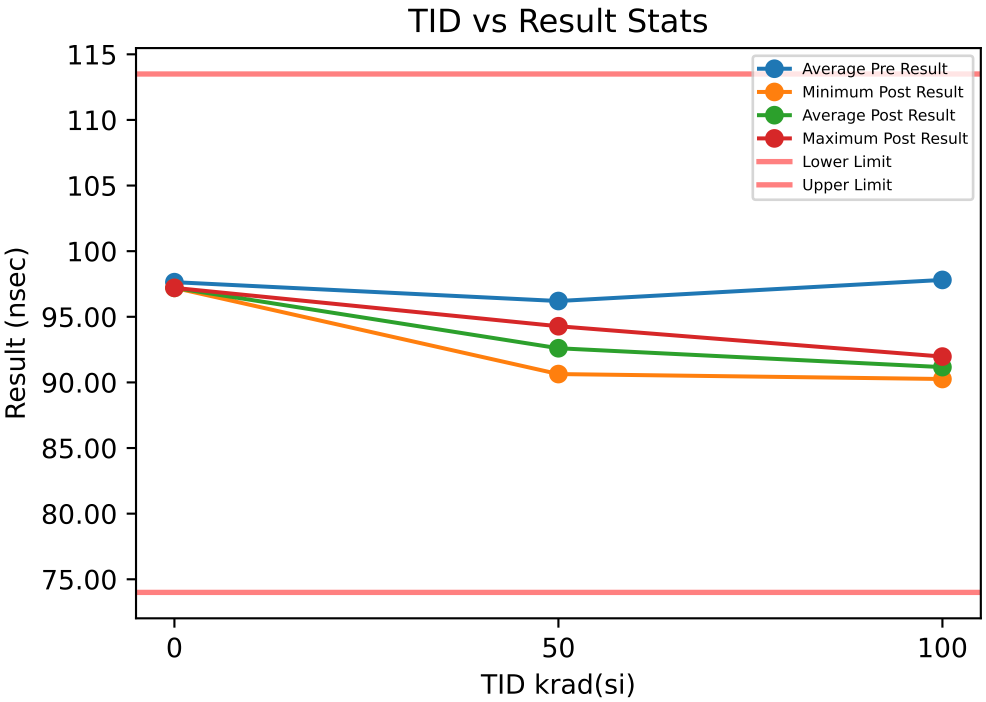
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

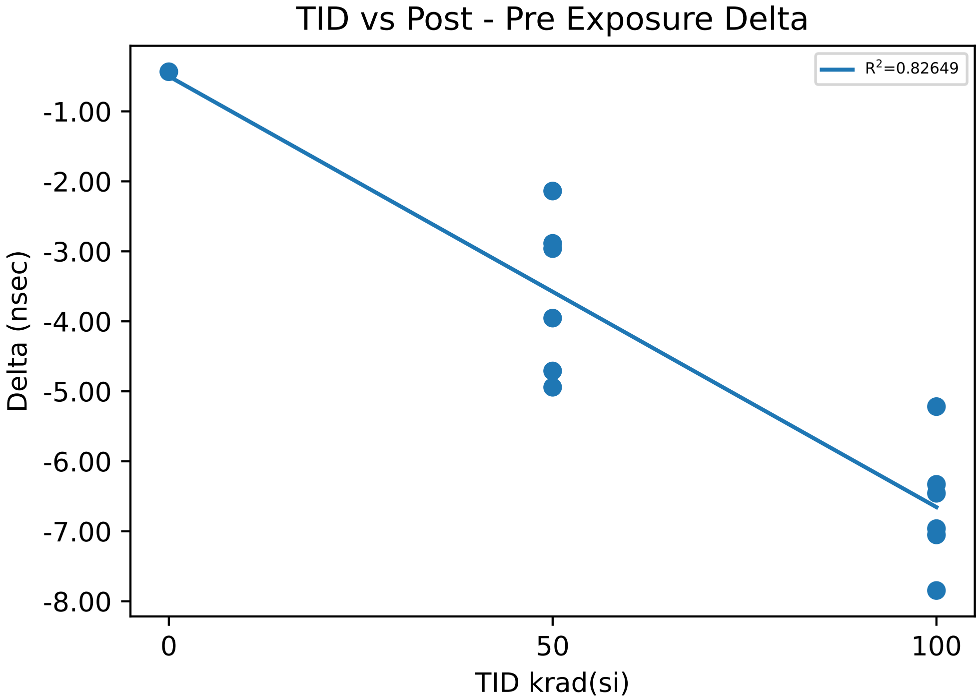
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	49.354	48.817	-0.5369
60	50	Biased	49.348	46.633	-2.7145
61	50	Biased	49.179	48.269	-0.9106
63	100	Biased	48.88	46.833	-2.0465
64	100	Biased	49.806	47.097	-2.7086
65	100	Biased	50.531	47.663	-2.867
66	50	Unbiased	49.991	47.463	-2.5273
67	50	Unbiased	49.312	48.397	-0.9157
68	50	Unbiased	49.95	47.749	-2.2003
69	100	Unbiased	50.49	47.676	-2.8136
70	100	Unbiased	50.536	46.495	-4.0406
71	100	Unbiased	49.659	47.334	-2.3245
72	0	Control	50.137	49.565	-0.5716

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.137	50.137	50.137		49.565	49.565	49.565		-0.5716	-0.5716	-0.5716	
50	49.179	49.522	49.991	0.35283	46.633	47.888	48.817	0.77983	-2.7145	-1.6342	-0.5369	0.95174
100	48.88	49.984	50.536	0.66565	46.495	47.183	47.676	0.4689	-4.0406	-2.8001	-2.0465	0.68498

Device Test: 97.9 DLH Dead Time Max 1MHz VIN_14V





Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
59	50	Biased	96.419	94.281	-2.1384
60	50	Biased	95.578	90.636	-4.9419
61	50	Biased	95.74	92.779	-2.9608
63	100	Biased	95.677	90.459	-5.2183
64	100	Biased	96.717	90.26	-6.457
65	100	Biased	98.93	91.969	-6.9615
66	50	Unbiased	96.531	91.822	-4.7091
67	50	Unbiased	96.279	93.393	-2.8857
68	50	Unbiased	96.664	92.71	-3.9539
69	100	Unbiased	98.591	91.539	-7.0513
70	100	Unbiased	98.656	90.81	-7.846
71	100	Unbiased	98.283	91.954	-6.3291
72	0	Control	97.639	97.205	-0.4341

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.639	97.639	97.639		97.205	97.205	97.205		-0.4341	-0.4341	-0.4341	
50	95.578	96.202	96.664	0.44213	90.636	92.604	94.281	1.2617	-4.9419	-3.5983	-2.1384	1.1145
100	95.677	97.809	98.93	1.3073	90.26	91.165	91.969	0.75519	-7.846	-6.6439	-5.2183	0.88071

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